



Product Characterization Report

for the

SP213 Family of Products

**SP204, SP207, SP208, SP211, SP213, SP238, and SP241
Products**

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Date: August 21, 2006**

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SP213
Product Family
Characterization Report

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Introduction: This product family characterization was done as part of the qualification of Sipex's fabrication site transfer from Sipex's Hillview Fab in Milpitas, CA, to a contract foundry, Episil, in Taiwan. This characterization report summarizes data for key SP213 product family characteristics and contains distributions for all parameters. A complete listing of the product numbers covered by the characterization report is included in the "Conclusion" section of this report. The distributions in Appendix A are arranged so that the Hillview and Episil distributions for a given parameter are adjacent. A distribution for a given parameter shows all of the temperature data combined at a given Vcc. Distributions for parameters with Vcc = 4.5V are followed by the distributions for Vcc = 5.0V which are followed by distributions for Vcc = 5.5V.

Wafer Fab: Episil
Fab Location: Taiwan
Process: Episil - 1x - SC2- mah - a
MS: 1584
Assembly location: Carsem

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Characterization Procedure:

Episil Lot number(s): 24634C
Hillview Lot number(s): 213L2
Temperatures: Ambient (25C), 85C, -40C
Tester: LTX
Test Program: SP213ECH.AT



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Data Summary:

Key Parameter Across Temperature Data Summary

Key Parameter	Units	Hillview Fab Distribution Mean	Hillview Fab Distribution Variance	Hillview Fab Cpk (across temp)		Episil Fab Distribution Mean	Episil Fab Distribution Variance	Episil Fab Cpk (across temp)
1: Icc No Load@ 4.5V Vcc	uA	499.39	105.099	>4.0000		390.665	104.879	>4.0000
4.004: TX1 Voh 3K @ 4.5V Vcc	v	5.840	62.395E-03	>4.0000		5.971	45.641E-03	>4.0000
4.001: TX2 Vol 3K @ 4.5V Vcc	v	-5.954	74.640E-03	>4.0000		-5.985	60.794E-03	>4.0000
11: TX1 +SR 3K, 50PF @ 4.5V Vcc	v/s	13.953	1.776	1.3333		12.499	3.156	1.8487
11.004 TX1 -SR 3K, 50PF @ 4.5V Vcc	v/s	14.083	2.293	1.3333		13.171	4.416	1.2704
1: Icc No Load @ 5V Vcc	uA	568.493	108.454	>4.0000		406.655	81.244	>4.0000
4.004: TX1 Voh 3K @ 5V Vcc	v	5.872	65.816E-03	>4.0000		6.079	59.760E-03	>4.0000
4.001: TX2 Vol 3K @ 5V Vcc	v	-5.937	79.190E-03	>4.0000		-6.096	81.620E-03	>4.0000
11: TX1 +SR 3K, 50PF @ 5V Vcc	v/s	13.837	1.695	1.3742		11.285	2.117	2.9463
11.004 TX1 -SR 3K, 50PF @ 5V Vcc	v/s	14.028	2.472	1.2293		11.066	2.909	2.1698
1: Icc No Load @ 5.5V Vcc	uA	629.96	177.976	>4.0000		478.247	88.314	>4.0000
4.004: TX1 Voh 3K @ 5.5V Vcc	v	5.905	99.251E-03	>4.0000		6.175	62.041E-03	>4.0000
4.001: TX2 Vol 3K @ 5.5V Vcc	v	-5.987	75.952E-03	>4.0000		-6.045	205.408E-03	>4.0000
11: TX1 +SR 3K, 50PF @ 5.5V Vcc	v/s	13.364	2.117	1.0258		11.133	1.848	3.4037
11.004 TX1 -SR 3K, 50PF @ 5.5V Vcc	v/s	13.433	2.583	1.0999		11.175	2.630	2.3860



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Conclusion:

Characterization data over temperature and Vcc range show datasheet parameters meet the spec. Cpk's for most parameters are comparable between Hillview and Episil although many show a strong temperature dependence that tends to produce lower Cpk's in this analysis.

The performance of SP213 parts fabricated at Episil are comparable to the current SP213 parts built from the Hillview fab.

This characterization report applies to the following SP213 family of product part numbers:

SP204EP-L	SP208CP-L	SP208EHCP-L	SP211CA-L	SP211EHET-L	SP238ACS-L
SP207EHCA	SP208CT	SP208EHCT	SP211CT	SP211ET	SP238ACT
SP207EHCA-L	SP208CT-L	SP208EHCT-L	SP211CT-L	SP211ET-L	SP238ACT-L
SP207EHEA	SP208EA	SP208EHEA	SP211EA	SP211HCA	SP238AES
SP207EHEA-L	SP208EA-L	SP208EHEA-L	SP211EA-L	SP211HCA-L	SP238AES-L
SP207EHET	SP208ECA	SP208EHEP	SP211ECA	SP211HCT	SP238AET
SP207EHET-L	SP208ECA-L	SP208EHEP-L	SP211ECA-L	SP211HCT-L	SP238AET-L
SP207HCP	SP208ECP	SP208EHET	SP211ECT	SP211HEA	SP241BCT
SP207HCP-L	SP208ECP-L	SP208EHET-L	SP211ECT-L	SP211HEA-L	SP241BCT-L
SP207HCT	SP208ECT	SP208EP	SP211EEA	SP211HET	SP241BET
SP207HCT-L	SP208ECT-L	SP208EP-L	SP211EEA-L	SP211HET-L	SP241BET-L
SP207HEA	SP208EEA	SP208ET	SP211EET	SP213EHCA	SP241CCT
SP207HEA-L	SP208EEA-L	SP208ET-L	SP211EET-L	SP213EHCA-L	SP241CCT-L
SP207HEP	SP208EEP	SP211BCA	SP211EHCA	SP213EHCT	SP241MCT
SP207HEP-L	SP208EEP-L	SP211BCA-L	SP211EHCA-L	SP213EHCT-L	SP241MCT-L
SP207HET	SP208EET	SP211BCT	SP211EHCT	SP213EHEA	
SP207HET-L	SP208EET-L	SP211BCT-L	SP211EHCT-L	SP213EHEA-L	
SP208CA	SP208EHCA	SP211BET	SP211EHEA	SP213EHET	
SP208CA-L	SP208EHCA-L	SP211BET-L	SP211EHEA-L	SP213EHET-L	
SP208CP	SP208EHCP	SP211CA	SP211EHET	SP238ACS	



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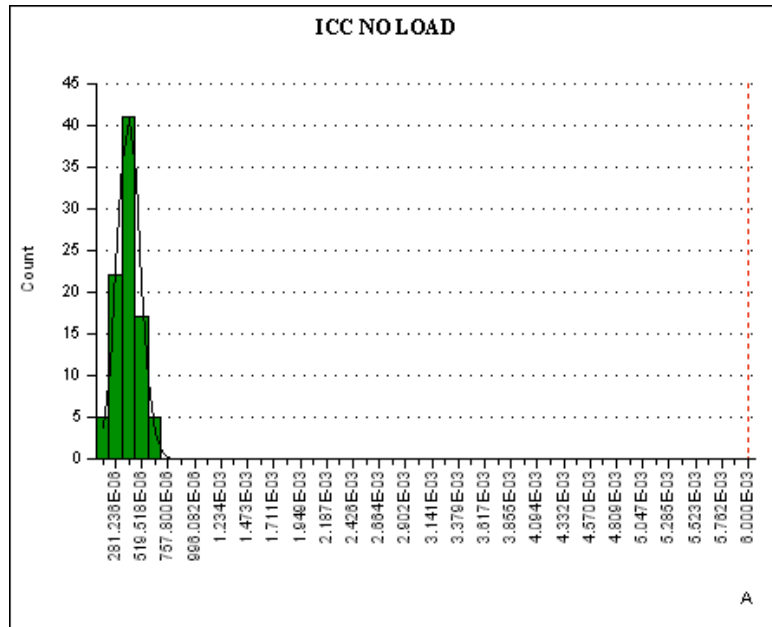
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Appendix A

Characterization Data Histograms

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Test.Number=1.000, Test.Name=ICC NO LOAD



Statistics: (A)

Max	652.690E-06	25%	328.458E-06	SpecHigh	6.000E-03
Mean	390.665E-06	10%	256.849E-06	SpecLow	N/A
Min	162.095E-06	N	90	PctWithinSpec	100.00
Range	490.595E-06	Cp	N/A	c	
StdDev	104.879E-06	Cpl	N/A	PctDefSpec	0
W	0.9799	Cpu	>4.0000	NWithinSpec	90
WpValue	0.1774	Cpk	>4.0000	NOutsideSpec	0
90%	527.052E-06	Skew	0.2816		
75%	447.746E-06	Kurtosis	0.0484		
Median	376.094E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

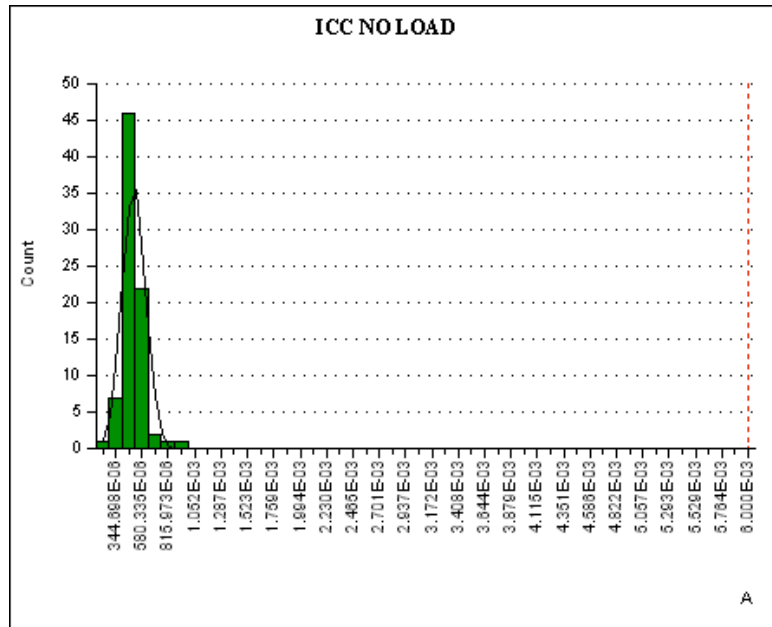
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StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=1.000, Test.Name=ICC NO LOAD



Statistics: (A)

Max	919.839E-06	25%	438.059E-06	SpecHigh	6.000E-03
Mean	499.392E-06	10%	399.080E-06	SpecLow	N/A
Min	226.879E-06	N	80	PctWithinSpec	100.00
Range	692.960E-06	Cp	N/A	c	
StdDev	105.099E-06	Cpl	N/A	PctDefSpec	0
W	0.9238	Cpu	>4.0000	NWithinSpec	80
WpValue	0.0001	Cpk	>4.0000	NOutsideSpec	0
90%	623.534E-06	Skew	1.1239		
75%	551.572E-06	Kurtosis	3.6756		
Median	482.638E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

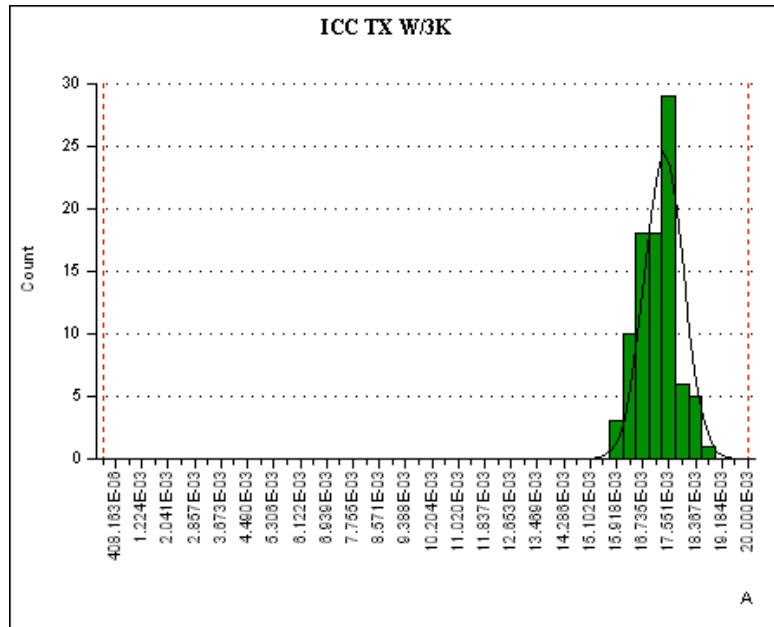
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=1.001, Test.Name=ICC TX W/3K



Statistics: (A)

Max	18.834E-03	25%	16.727E-03	SpecHigh	20.000E-03
Mean	17.208E-03	10%	16.504E-03	SpecLow	0
Min	15.791E-03	N	90	PctWithinSpec	100.00
Range	3.043E-03	Cp	>4.0000	PctDefSpec	0
StdDev	5.96503E-06	Cpl	>4.0000	NWithinSpec	90
W	0.9885	Cpu	1.5602	NOutsideSpec	0
WpValue	0.6176	Cpk	1.5602		
90%	17.914E-03	Skew	0.0143		
75%	17.643E-03	Kurtosis	-0.1028		
Median	17.282E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C:	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

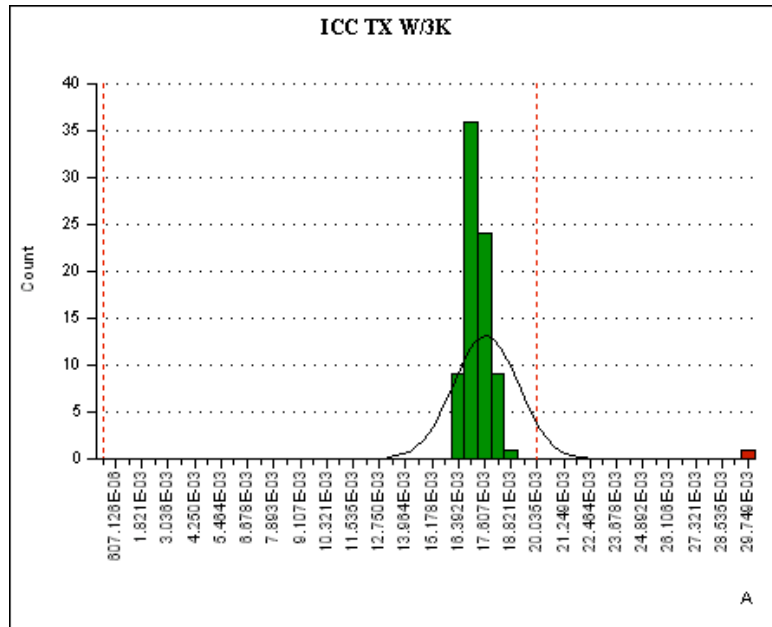
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StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=1.001, Test.Name=ICC TX W/3K



Statistics: (A)

Max	29.749E-03	25%	16.970E-03	SpecHigh	20.000E-03
Mean	17.460E-03	10%	16.688E-03	SpecLow	0
Min	16.165E-03	N	80	PctWithinSpec	98.75
Range	13.584E-03	Cp	2.2601	PctDefSpec	1.25
StdDev	1.475E-03	Cpl	3.9462	NWithinSpec	79
W	0.3526	Cpu	0.5741	NOutsideSpec	1
WpValue	0.0000	Cpk	0.5741		
90%	18.049E-03	Skew	7.4866		
75%	17.672E-03	Kurtosis	62.7558		
Median	17.236E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

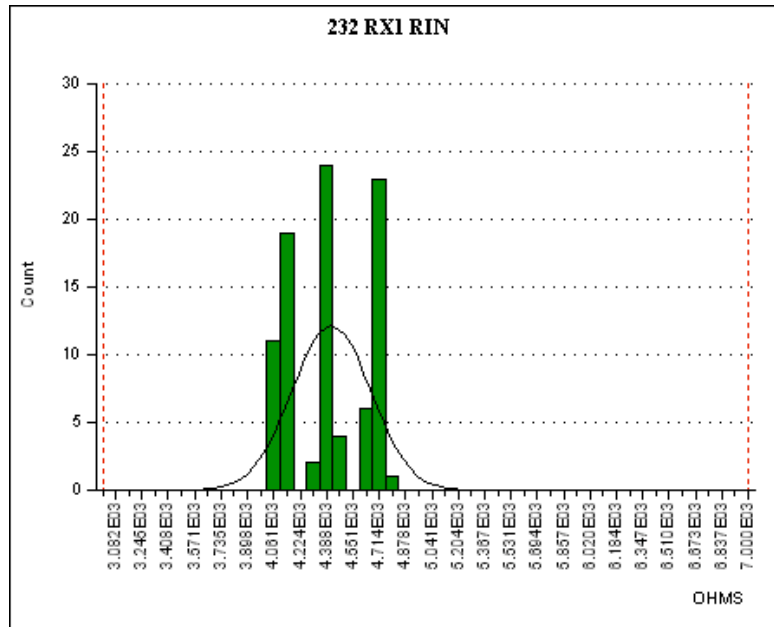
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=2.000, Test.Name=232 RX1 RIN



Statistics: (OHMS)

Max	4.759E03	25%	4.142E03	SpecHigh	7.000E03
Mean	4.400E03	10%	4.094E03	SpecLow	3.000E03
Min	4.056E03	N	90	PctWithinSpec	100.00
Range	702.397	Cp	2.7604	PctDefSpec	0
StdDev	241.511	Cpl	1.9320	NWithinSpec	90
W	0.8788	Cpu	3.5888	NOutsideSpec	0
WpValue	0.0000	Cpk	1.9320		
90%	4.706E03	Skew	0.0552		
75%	4.678E03	Kurtosis	-1.4551		
Median	4.387E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

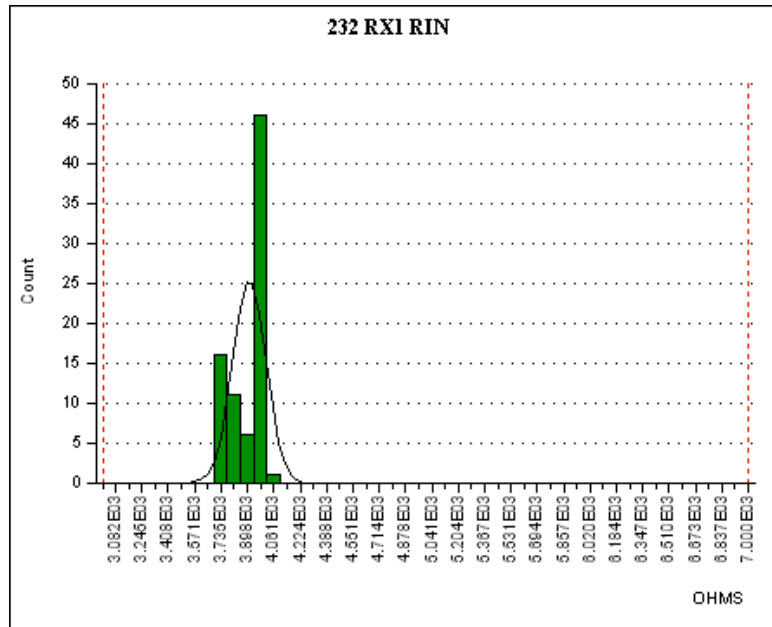
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=2.000, Test.Name=232 RX1 RIN



Statistics: (OHMS)

Max	4.038E03	25%	3.789E03	SpecHigh	7.000E03
Mean	3.897E03	10%	3.734E03	SpecLow	3.000E03
Min	3.700E03	N	80	PctWithinSpec	100.00
Range	338.257	Cp	>4.0000	PctDefSpec	0
StdDev	101.954	Cpl	2.9313	NWithinSpec	80
W	0.8405	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	2.9313		
90%	3.998E03	Skew	-0.6892		
75%	3.975E03	Kurtosis	-1.1313		
Median	3.947E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

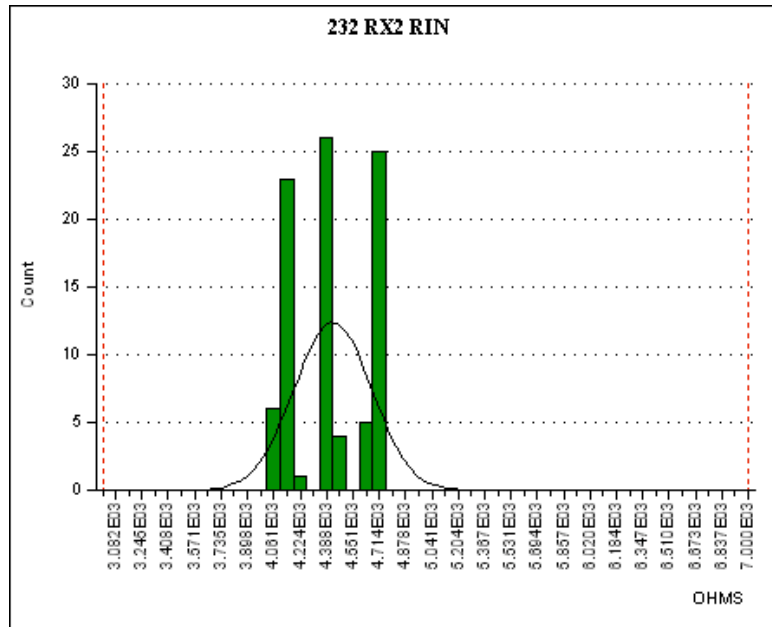
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=2.001, Test.Name=232 RX2 RIN



Statistics: (OHMS)

Max	4.755E03	25%	4.141E03	SpecHigh	7.000E03
Mean	4.409E03	10%	4.109E03	SpecLow	3.000E03
Min	4.077E03	N	90	PctWithinSpec	100.00
Range	677.741	Cp	2.8200	c	
StdDev	236.409	Cpl	1.9866	PctDefSpec	0
W	0.8681	Cpu	3.6534	NWithinSpec	90
WpValue	0.0000	Cpk	1.9866	NOutsideSpec	0
90%	4.712E03	Skew	0.0613		
75%	4.681E03	Kurtosis	-1.4697		
Median	4.393E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

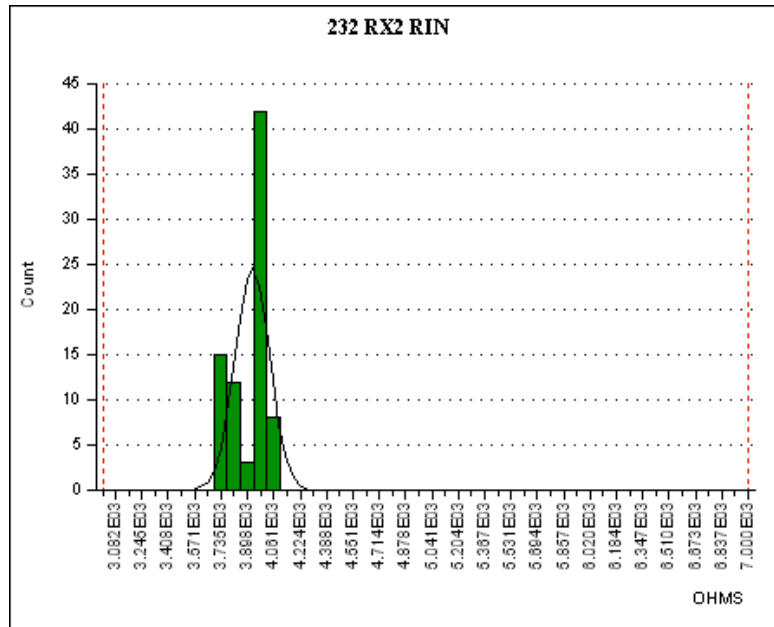
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=2.001, Test.Name=232 RX2 RIN



Statistics: (OHMS)

Max	4.059E03	25%	3.828E03	SpecHigh	7.000E03
Mean	3.915E03	10%	3.747E03	SpecLow	3.000E03
Min	3.718E03	N	80	PctWithinSpec	100.00
Range	341.033	Cp	>4.0000	c	
StdDev	106.063	Cpl	2.8758	PctDefSpec	0
W	0.8537	Cpu	>4.0000	NWithinSpec	80
WpValue	0.0000	Cpk	2.8758	NOutsideSpec	0
90%	4.018E03	Skew	-0.6526		
75%	3.994E03	Kurtosis	-1.1247		
Median	3.966E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

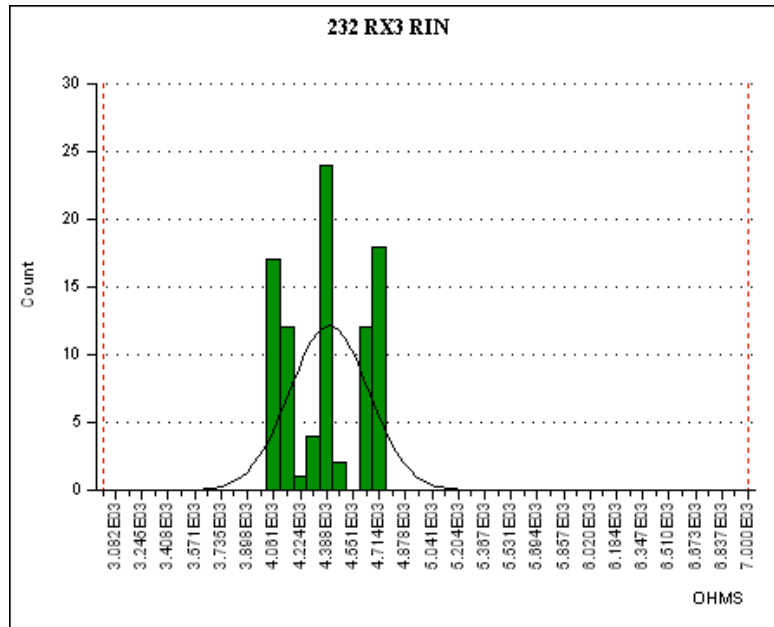
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=2.002, Test.Name=232 RX3 RIN



Statistics: (OHMS)

Max	4.751E03	25%	4.121E03	SpecHigh	7.000E03
Mean	4.386E03	10%	4.082E03	SpecLow	3.000E03
Min	4.027E03	N	90	PctWithinSpec	100.00
Range	724.158	Cp	2.7663	PctDefSpec	0
StdDev	240.992	Cpl	1.9177	NWithinSpec	90
W	0.8825	Cpu	3.6150	NOutsideSpec	0
WpValue	0.0000	Cpk	1.9177		
90%	4.693E03	Skew	0.0554		
75%	4.666E03	Kurtosis	-1.4471		
Median	4.371E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

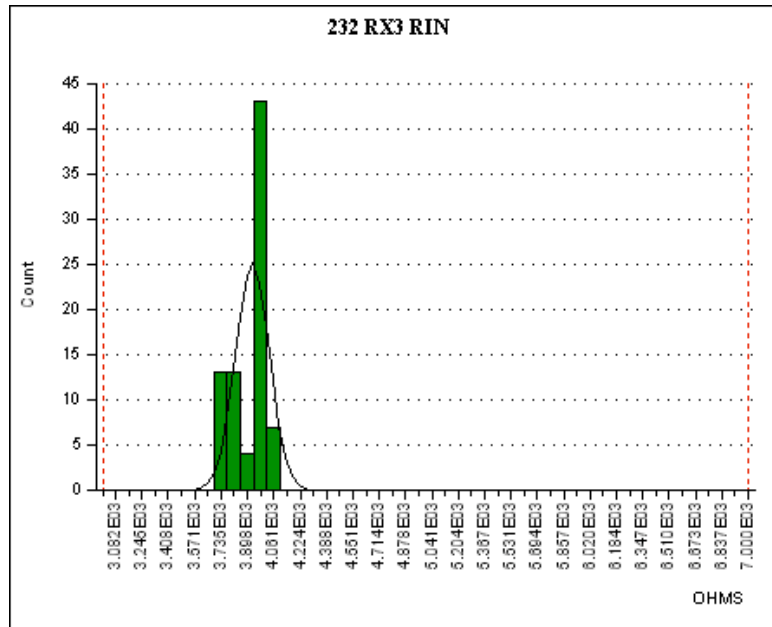
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=2.002, Test.Name=232 RX3 RIN



Statistics: (OHMS)

Max	4.052E03	25%	3.823E03	SpecHigh	7.000E03
Mean	3.916E03	10%	3.749E03	SpecLow	3.000E03
Min	3.722E03	N	80	PctWithinSpec	100.00
Range	329.332	Cp	>4.0000	c	
StdDev	103.521	Cpl	2.9484	PctDefSpec	0
W	0.8603	Cpu	>4.0000	NWithinSpec	80
WpValue	0.0000	Cpk	2.9484	NOutsideSpec	0
90%	4.019E03	Skew	-0.6428		
75%	3.992E03	Kurtosis	-1.1127		
Median	3.964E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

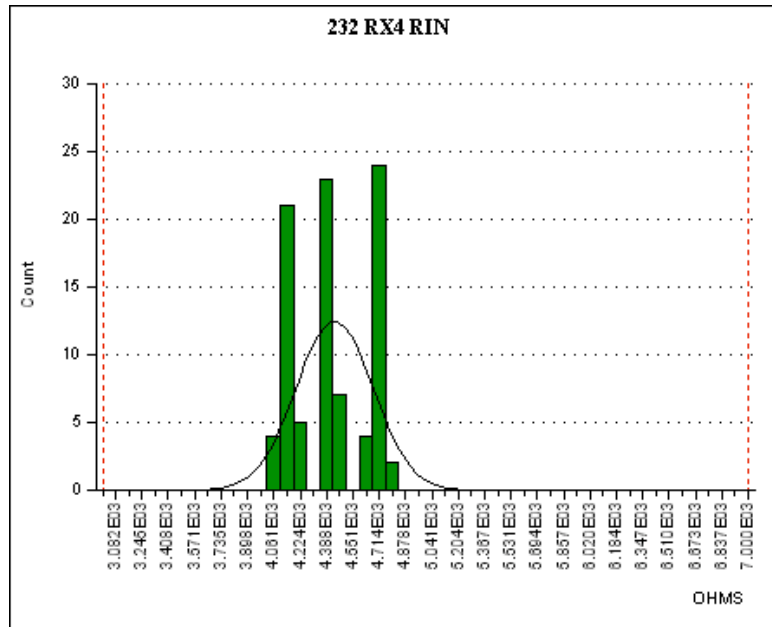
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=2.003, Test.Name=232 RX4 RIN



Statistics: (OHMS)

Max	4.770E03	25%	4.171E03	SpecHigh	7.000E03
Mean	4.420E03	10%	4.117E03	SpecLow	3.000E03
Min	4.074E03	N	90	PctWithinSpec	100.00
Range	696.718	Cp	2.8410	PctDefSpec	0
StdDev	234.658	Cpl	2.0166	NWithinSpec	90
W	0.8797	Cpu	3.6654	NOutsideSpec	0
WpValue	0.0000	Cpk	2.0166		
90%	4.723E03	Skew	0.0649		
75%	4.687E03	Kurtosis	-1.4533		
Median	4.405E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

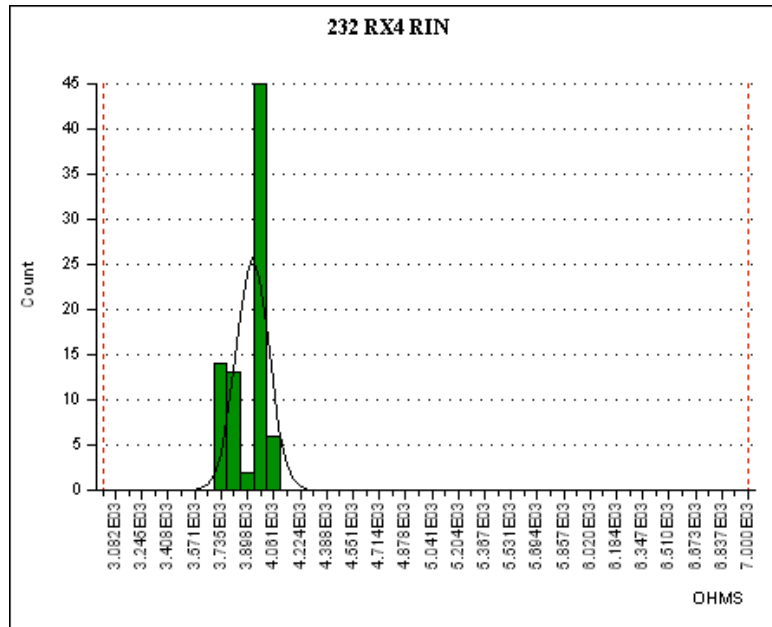
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=2.003, Test.Name=232 RX4 RIN



Statistics: (OHMS)

Max	4.040E03	25%	3.817E03	SpecHigh	7.000E03
Mean	3.916E03	10%	3.752E03	SpecLow	3.000E03
Min	3.719E03	N	80	PctWithinSpec	100.00
Range	320.350	Cp	>4.0000	c	
StdDev	101.369	Cpl	3.0121	PctDefSpec	0
W	0.8505	Cpu	>4.0000	NWithinSpec	80
WpValue	0.0000	Cpk	3.0121	NOutsideSpec	0
90%	4.015E03	Skew	-0.6791		
75%	3.996E03	Kurtosis	-1.1051		
Median	3.961E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

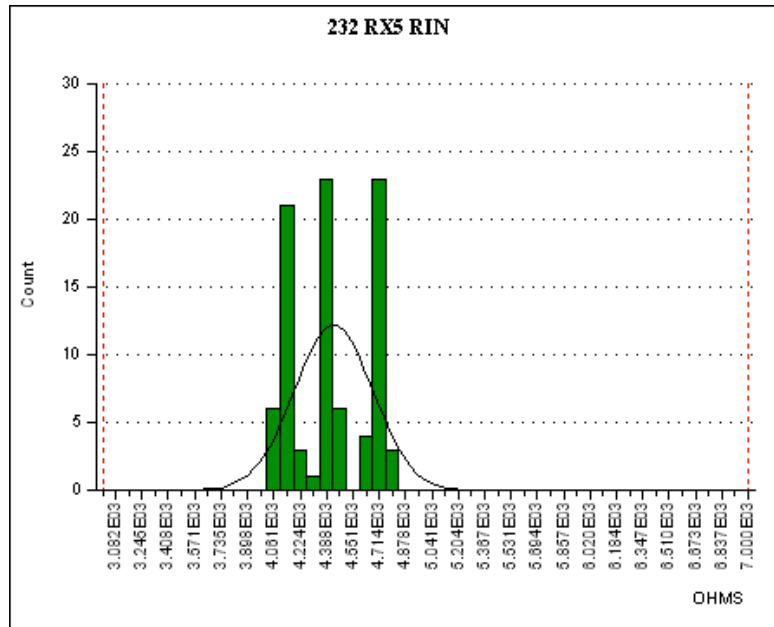
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=2.004, Test.Name=232 RX5 RIN



Statistics: (OHMS)

Max	4.769E03	25%	4.157E03	SpecHigh	7.000E03
Mean	4.414E03	10%	4.113E03	SpecLow	3.000E03
Min	4.060E03	N	90	PctWithinSpec	100.00
Range	708.770	Cp	2.7739	PctDefSpec	0
StdDev	240.340	Cpl	1.9606	NWithinSpec	90
W	0.8781	Cpu	3.5871	NOutsideSpec	0
WpValue	0.0000	Cpk	1.9606		
90%	4.721E03	Skew	0.0628		
75%	4.692E03	Kurtosis	-1.4564		
Median	4.400E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

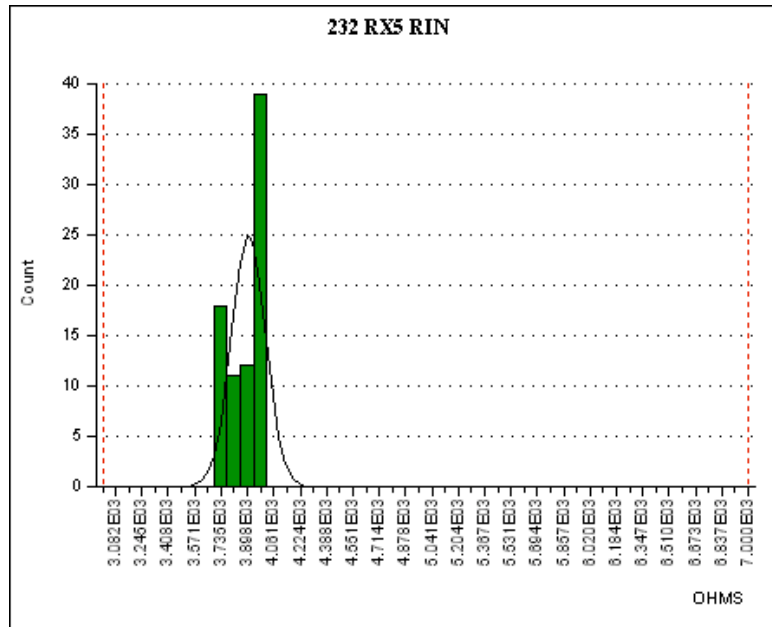
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=2.004, Test.Name=232 RX5 RIN



Statistics: (OHMS)

Max	4.017E03	25%	3.791E03	SpecHigh	7.000E03
Mean	3.891E03	10%	3.725E03	SpecLow	3.000E03
Min	3.697E03	N	80	PctWithinSpec	100.00
Range	319.966	Cp	>4.0000	PctDefSpec	0
StdDev	103.379	Cpl	2.8736	NWithinSpec	80
W	0.8361	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	2.8736		
90%	3.992E03	Skew	-0.6895		
75%	3.971E03	Kurtosis	-1.1468		
Median	3.938E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

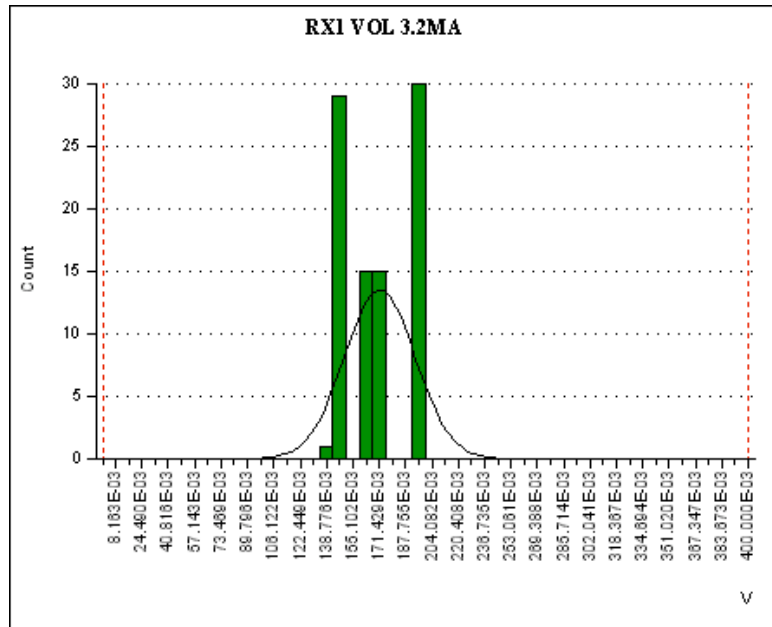
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.000, Test.Name=RX1 VOL 3.2MA



Statistics: (V)

Max	198.746E-03	25%	145.389E-03	SpecHigh	400.000E-03
Mean	169.756E-03	10%	143.768E-03	SpecLow	0
Min	142.796E-03	N	90	PctWithinSpec	100.00
Range	55.950E-03	Cp	3.0799	PctDefSpec	0
StdDev	21.646E-03	Cpl	2.6142	NWithinSpec	90
W	0.8201	Cpu	3.5457	NOutsideSpec	0
WpValue	0.0000	Cpk	2.6142		
90%	197.660E-03	Skew	0.1695		
75%	196.878E-03	Kurtosis	-1.5062		
Median	167.371E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

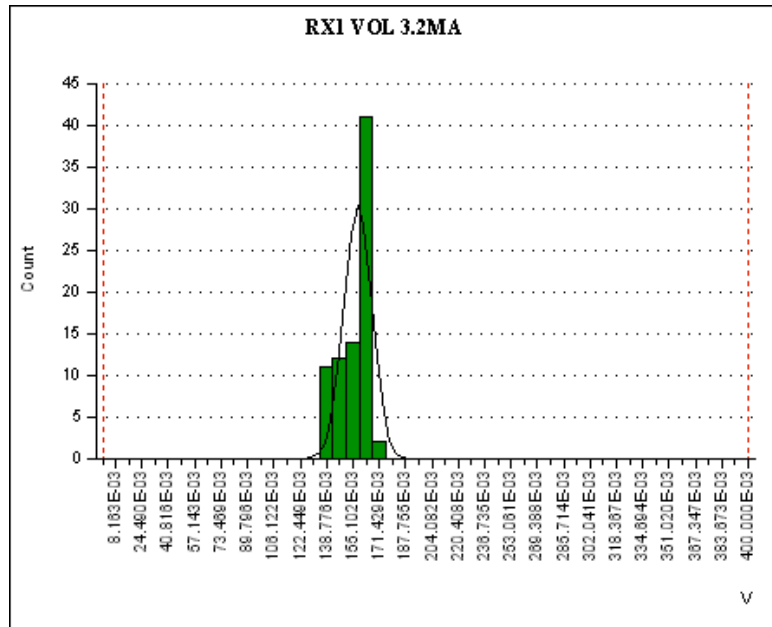
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=3.000, Test.Name=RX1 VOL 3.2MA



Statistics: (V)

Max	169.212E-03	25%	149.832E-03	SpecHigh	400.000E-03
Mean	156.337E-03	10%	141.656E-03	SpecLow	0
Min	138.188E-03	N	80	PctWithinSpec	100.00
Range	31.023E-03	Cp	>4.0000	PctDefSpec	0
StdDev	8.534E-03	Cpl	>4.0000	NWithinSpec	80
W	0.8766	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	164.085E-03	Skew	-0.7986		
75%	162.713E-03	Kurtosis	-0.6535		
Median	159.379E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

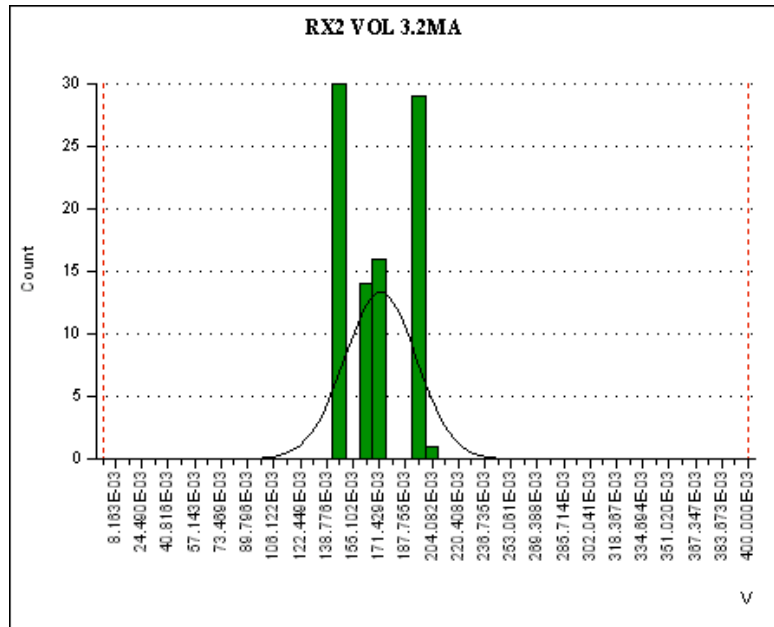
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.001, Test.Name=RX2 VOL 3.2MA



Statistics: (V)

Max	200.271E-03	25%	145.503E-03	SpecHigh	400.000E-03
Mean	170.149E-03	10%	143.768E-03	SpecLow	0
Min	142.910E-03	N	90	PctWithinSpec	100.00
Range	57.361E-03	Cp	3.0380	PctDefSpec	0
StdDev	21.944E-03	Cpl	2.5846	NWithinSpec	90
W	0.8240	Cpu	3.4914	NOutsideSpec	0
WpValue	0.0000	Cpk	2.5846		
90%	198.727E-03	Skew	0.1734		
75%	197.221E-03	Kurtosis	-1.5028		
Median	167.466E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

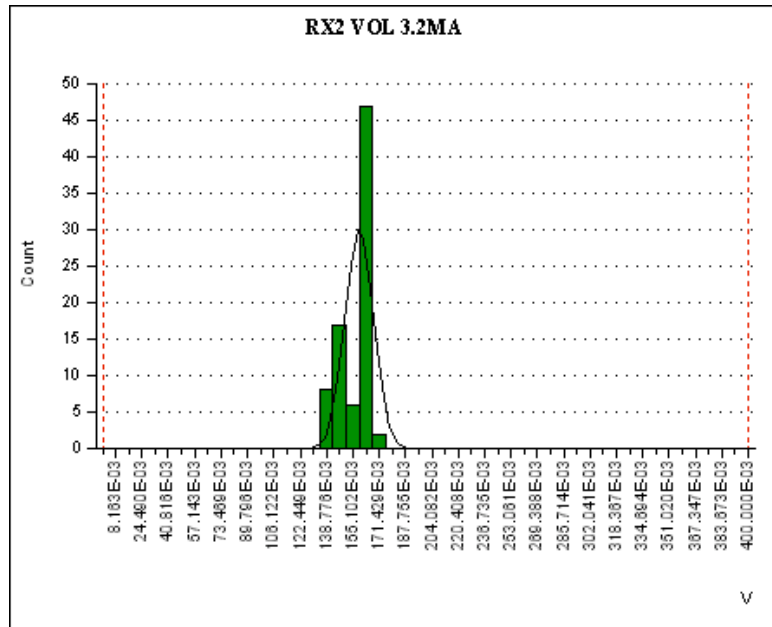
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=3.001, Test.Name=RX2 VOL 3.2MA



Statistics: (V)

Max	167.877E-03	25%	149.508E-03	SpecHigh	400.000E-03
Mean	157.119E-03	10%	143.295E-03	SpecLow	0
Min	139.218E-03	N	80	PctWithinSpec	100.00
Range	28.660E-03	Cp	>4.0000	c	
StdDev	8.637E-03	Cpl	>4.0000	PctDefSpec	0
W	0.8582	Cpu	>4.0000	NWithinSpec	80
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	165.344E-03	Skew	-0.7163		
75%	164.162E-03	Kurtosis	-0.9948		
Median	160.904E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

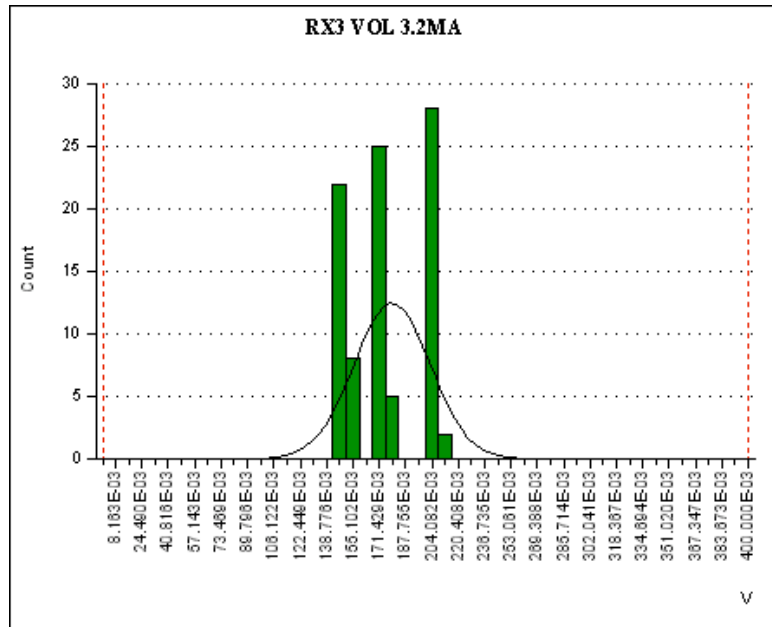
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.002, Test.Name=RX3 VOL 3.2MA



Statistics: (V)

Max	209.266E-03	25%	151.526E-03	SpecHigh	400.000E-03
Mean	177.260E-03	10%	149.314E-03	SpecLow	0
Min	147.789E-03	N	90	PctWithinSpec	100.00
Range	61.477E-03	Cp	2.8448	PctDefSpec	0
StdDev	23.435E-03	Cpl	2.5213	NWithinSpec	90
W	0.8223	Cpu	3.1682	NOutsideSpec	0
WpValue	0.0000	Cpk	2.5213		
90%	207.683E-03	Skew	0.1738		
75%	206.330E-03	Kurtosis	-1.5047		
Median	174.441E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

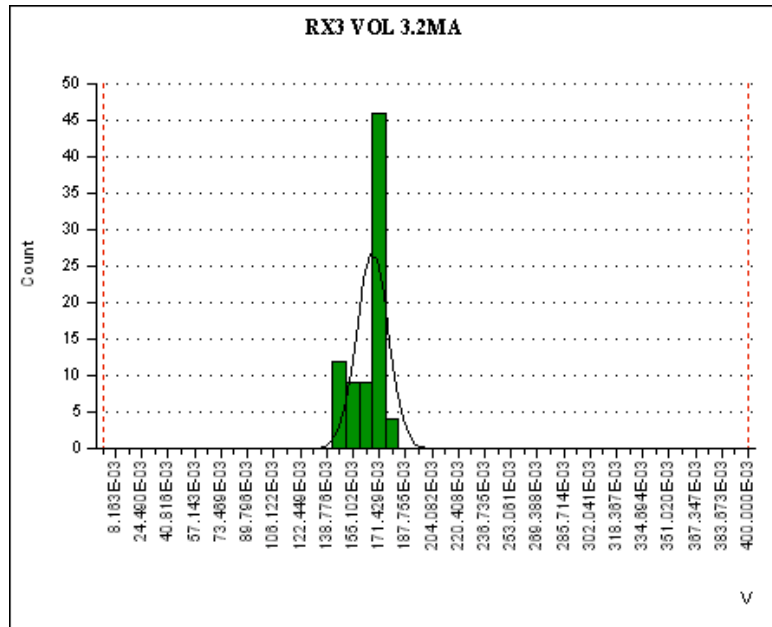
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=3.002, Test.Name=RX3 VOL 3.2MA



Statistics: (V)

Max	177.024E-03	25%	156.292E-03	SpecHigh	400.000E-03
Mean	165.254E-03	10%	149.165E-03	SpecLow	0
Min	145.316E-03	N	80	PctWithinSpec	100.00
Range	31.708E-03	Cp	>4.0000	c	
StdDev	9.682E-03	Cpl	>4.0000	PctDefSpec	0
W	0.8362	Cpu	>4.0000	NWithinSpec	80
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	174.547E-03	Skew	-0.7475		
75%	172.623E-03	Kurtosis	-1.0304		
Median	169.593E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

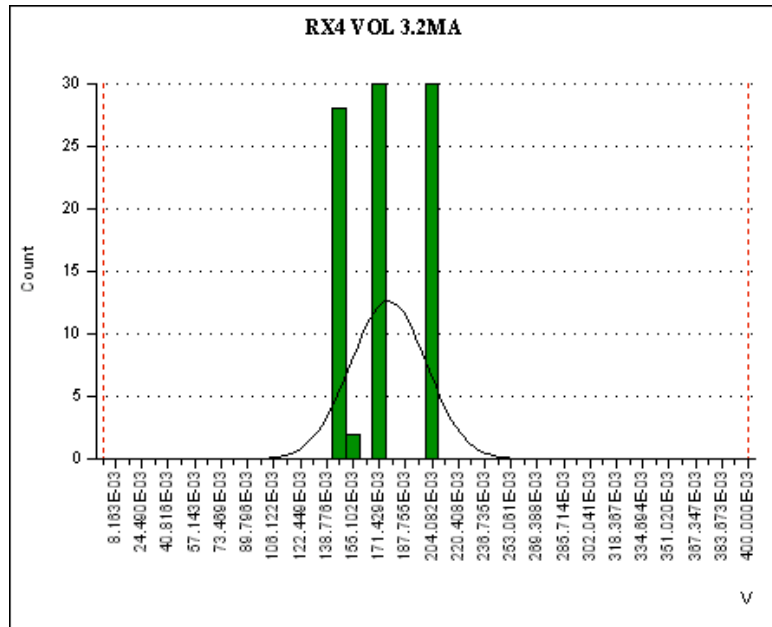
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.003, Test.Name=RX4 VOL 3.2MA



Statistics: (V)

Max	206.482E-03	25%	148.895E-03	SpecHigh	400.000E-03
Mean	175.043E-03	10%	147.181E-03	SpecLow	0
Min	145.999E-03	N	90	PctWithinSpec	100.00
Range	60.483E-03	Cp	2.8840	PctDefSpec	0
StdDev	23.116E-03	Cpl	2.5241	NWithinSpec	90
W	0.8219	Cpu	3.2438	NOutsideSpec	0
WpValue	0.0000	Cpk	2.5241		
90%	204.997E-03	Skew	0.1682		
75%	203.625E-03	Kurtosis	-1.5049		
Median	172.460E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C:	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

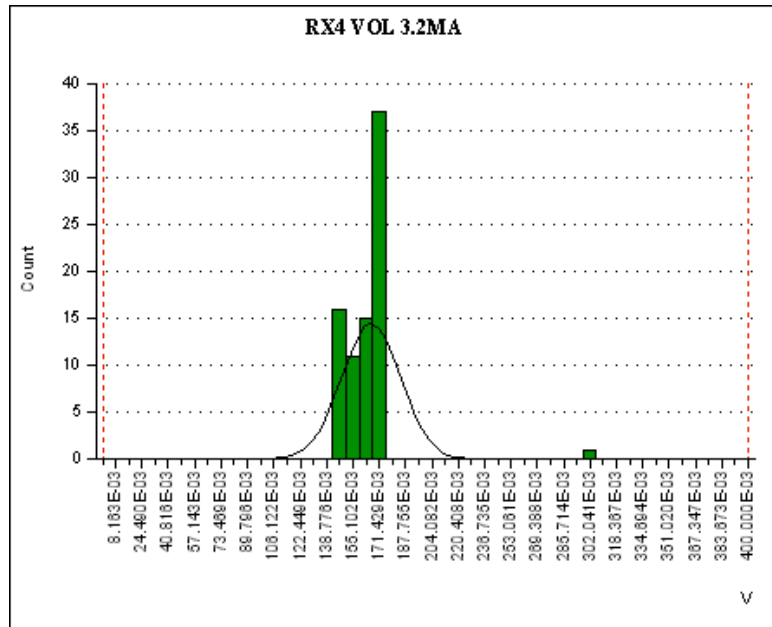
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=3.003, Test.Name=RX4 VOL 3.2MA



Statistics: (V)

Max	301.306E-03	25%	154.805E-03	SpecHigh	400.000E-03
Mean	164.441E-03	10%	147.182E-03	SpecLow	0
Min	143.105E-03	N	80	PctWithinSpec	100.00
Range	158.202E-03	Cp	3.6945	c	
StdDev	18.045E-03	Cpl	3.0376	PctDefSpec	0
W	0.5068	Cpu	>4.0000	NWithinSpec	80
WpValue	0.0000	Cpk	3.0376	NOutsideSpec	0
90%	171.308E-03	Skew	5.4850		
75%	170.203E-03	Kurtosis	42.2873		
Median	166.524E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

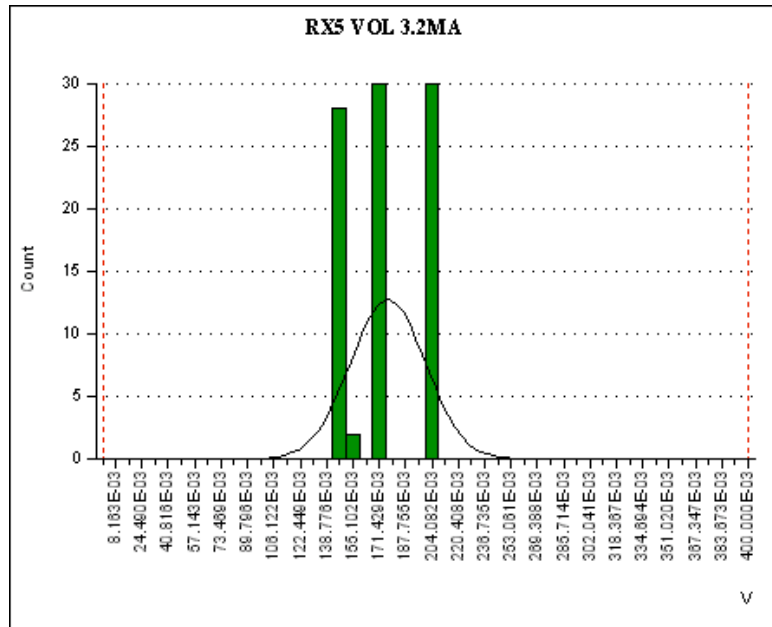
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.004, Test.Name=RX5 VOL 3.2MA



Statistics: (V)

Max	206.635E-03	25%	148.780E-03	SpecHigh	400.000E-03
Mean	174.722E-03	10%	147.162E-03	SpecLow	0
Min	146.037E-03	N	90	PctWithinSpec	100.00
Range	60.598E-03	Cp	2.8966	PctDefSpec	0
StdDev	23.016E-03	Cpl	2.5305	NWithinSpec	90
W	0.8217	Cpu	3.2627	NOutsideSpec	0
WpValue	0.0000	Cpk	2.5305		
90%	204.368E-03	Skew	0.1683		
75%	203.281E-03	Kurtosis	-1.5049		
Median	171.926E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

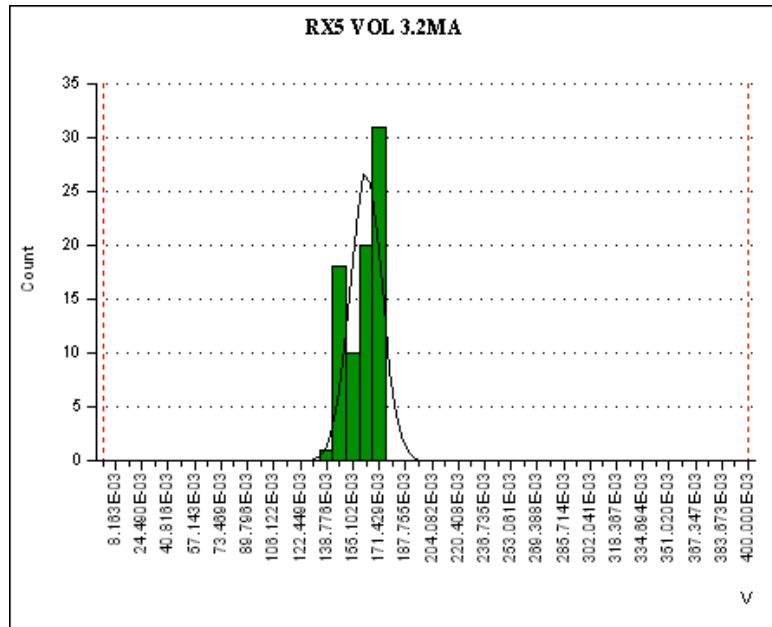
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=3.004, Test.Name=RX5 VOL 3.2MA



Statistics: (V)

Max	173.213E-03	25%	152.118E-03	SpecHigh	400.000E-03
Mean	161.235E-03	10%	145.639E-03	SpecLow	0
Min	142.266E-03	N	80	PctWithinSpec	100.00
Range	30.947E-03	Cp	>4.0000	PctDefSpec	0
StdDev	9.694E-03	Cpl	>4.0000	NWithinSpec	80
W	0.8373	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	170.756E-03	Skew	-0.6930		
75%	168.754E-03	Kurtosis	-1.1345		
Median	165.896E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

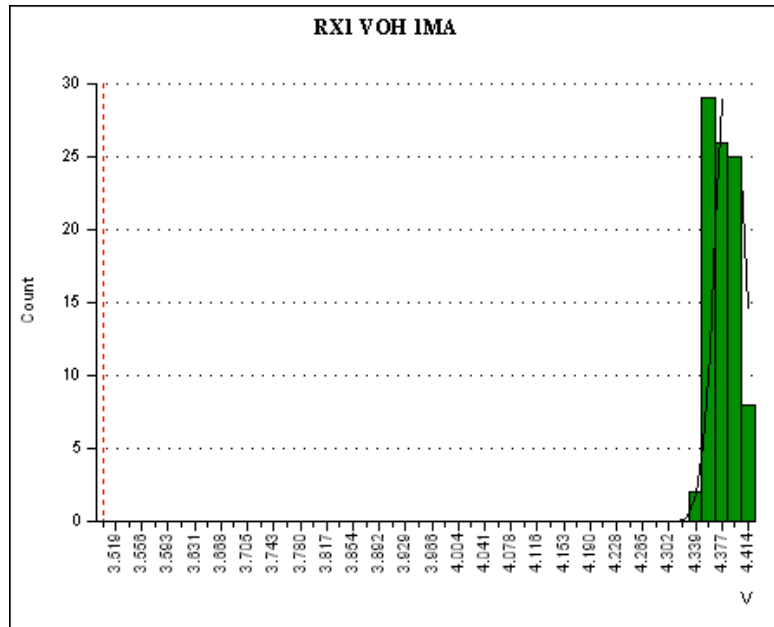
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.005, Test.Name=RX1 VOH 1MA



Statistics: (V)

Max	4.414	25%	4.357	SpecHigh	N/A
Mean	4.379	10%	4.353	SpecLow	3.500
Min	4.346	N	90	PctWithinSpec	100.00
Range	67.649E-03	Cp	N/A	c	
StdDev	19.903E-03	Cpl	>4.0000	PctDefSpec	0
W	0.9092	Cpu	N/A	NWithinSpec	90
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	4.404	Skew	-0.0601		
75%	4.400	Kurtosis	-1.4207		
Median	4.380				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

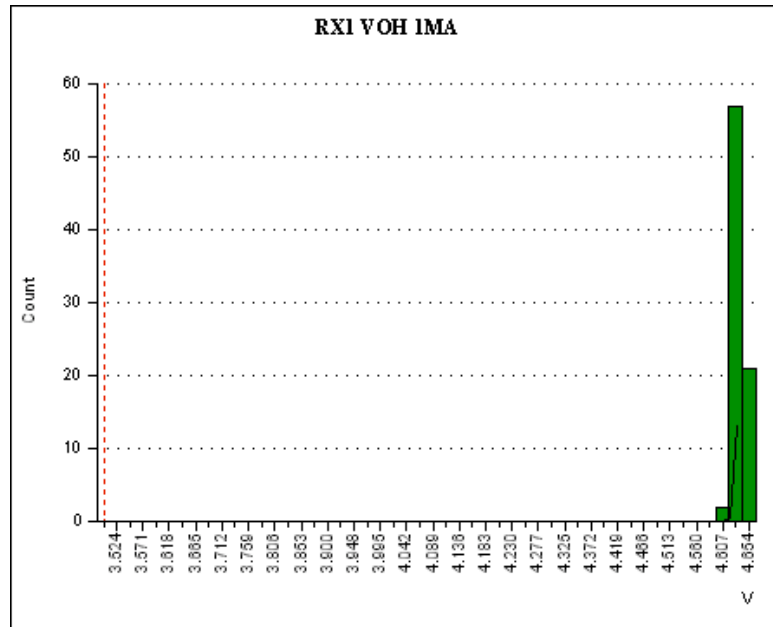
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=3.005, Test.Name=RX1 VOH 1MA



Statistics: (V)

Max	4.654	25%	4.631	SpecHigh	N/A
Mean	4.637	10%	4.627	SpecLow	3.500
Min	4.616	N	80	PctWithinSpec	100.00
Range	38.569E-03	Cp	N/A	PctDefSpec	0
StdDev	9.068E-03	Cpl	>4.0000	NWithinSpec	80
W	0.9789	Cpu	N/A	NOutsideSpec	0
WpValue	0.2071	Cpk	>4.0000		
90%	4.649	Skew	-0.0689		
75%	4.644	Kurtosis	-0.4423		
Median	4.637				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

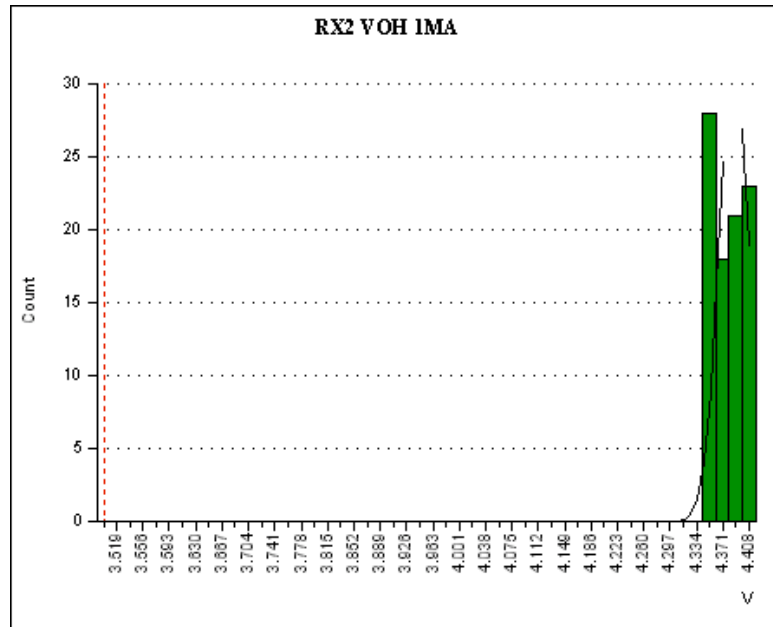
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.006, Test.Name=RX2 VOH 1MA



Statistics: (V)

Max	4.408	25%	4.355	SpecHigh	N/A
Mean	4.378	10%	4.350	SpecLow	3.500
Min	4.345	N	90	PctWithinSpec	100.00
Range	63.152E-03	Cp	N/A	c	
StdDev	20.807E-03	Cpl	>4.0000	PctDefSpec	0
W	0.9070	Cpu	N/A	NWithinSpec	90
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	4.405	Skew	-0.0876		
75%	4.399	Kurtosis	-1.4663		
Median	4.380				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

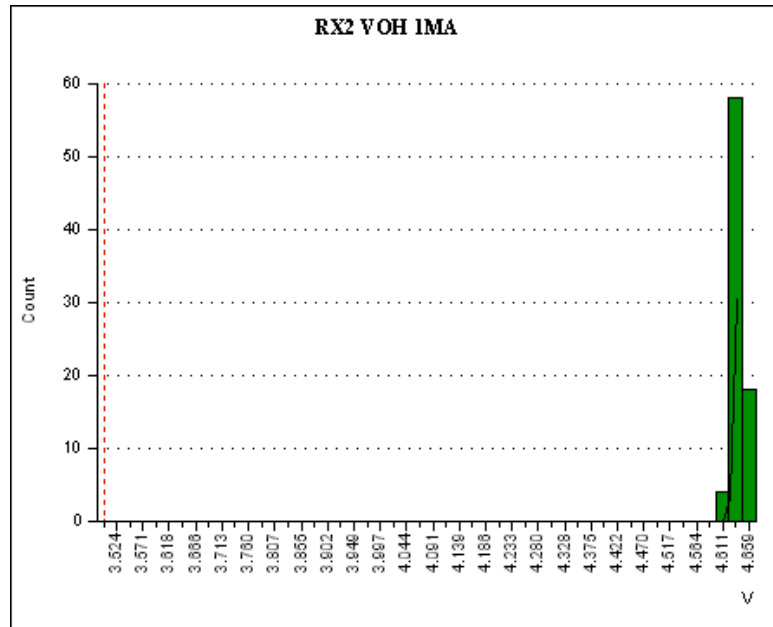
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=3.006, Test.Name=RX2 VOH 1MA



Statistics: (V)

Max	4.659	25%	4.630	SpecHigh	N/A
Mean	4.637	10%	4.625	SpecLow	3.500
Min	4.622	N	80	PctWithinSpec	100.00
Range	36.396E-03	Cp	N/A	PctDefSpec	0
StdDev	9.852E-03	Cpl	>4.0000	NWithinSpec	80
W	0.9509	Cpu	N/A	NOutsideSpec	0
WpValue	0.0039	Cpk	>4.0000		
90%	4.651	Skew	0.3973		
75%	4.646	Kurtosis	-0.9176		
Median	4.635				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

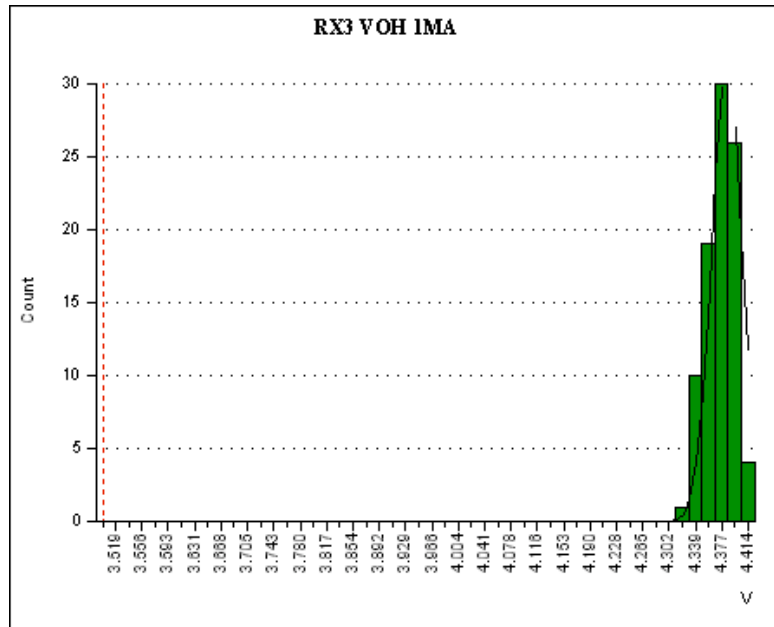
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.007, Test.Name=RX3 VOH 1MA



Statistics: (V)

Max	4.414	25%	4.354	SpecHigh	N/A
Mean	4.375	10%	4.342	SpecLow	3.500
Min	4.329	N	90	PctWithinSpec	100.00
Range	85.335E-03	Cp	N/A	PctDefSpec	0
StdDev	21.414E-03	Cpl	>4.0000	NWithinSpec	90
W	0.9436	Cpu	N/A	NOutsideSpec	0
WpValue	0.0007	Cpk	>4.0000		
90%	4.399	Skew	-0.4148		
75%	4.393	Kurtosis	-0.9272		
Median	4.381				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

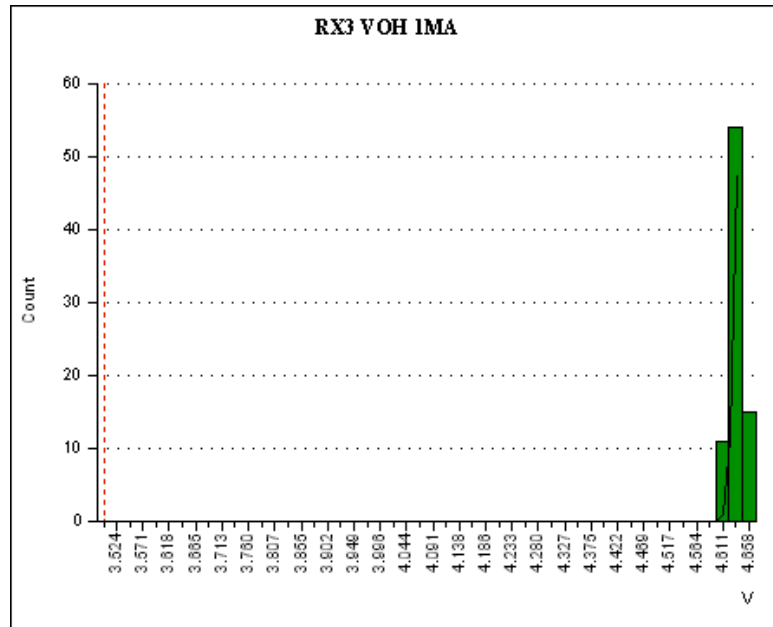
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=3.007, Test.Name=RX3 VOH 1MA



Statistics: (V)

Max	4.658	25%	4.626	SpecHigh	N/A
Mean	4.633	10%	4.620	SpecLow	3.500
Min	4.611	N	80	PctWithinSpec	100.00
Range	47.068E-03	Cp	N/A	c	
StdDev	11.131E-03	Cpl	>4.0000	PctDefSpec	0
W	0.9416	Cpu	N/A	NWithinSpec	80
WpValue	0.0012	Cpk	>4.0000	NOutsideSpec	0
90%	4.650	Skew	0.4476		
75%	4.643	Kurtosis	-0.7358		
Median	4.630				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

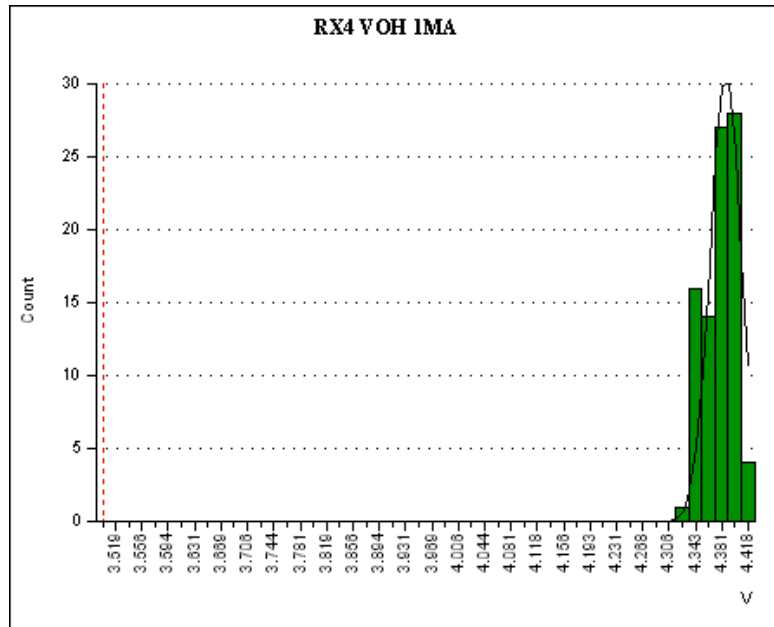
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.008, Test.Name=RX4 VOH 1MA



Statistics: (V)

Max	4.418	25%	4.356	SpecHigh	N/A
Mean	4.377	10%	4.345	SpecLow	3.500
Min	4.329	N	90	PctWithinSpec	100.00
Range	89.031E-03	Cp	N/A	PctDefSpec	0
StdDev	21.996E-03	Cpl	>4.0000	NWithinSpec	90
W	0.9474	Cpu	N/A	NOutsideSpec	0
WpValue	0.0012	Cpk	>4.0000		
90%	4.401	Skew	-0.2637		
75%	4.396	Kurtosis	-1.0288		
Median	4.381				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

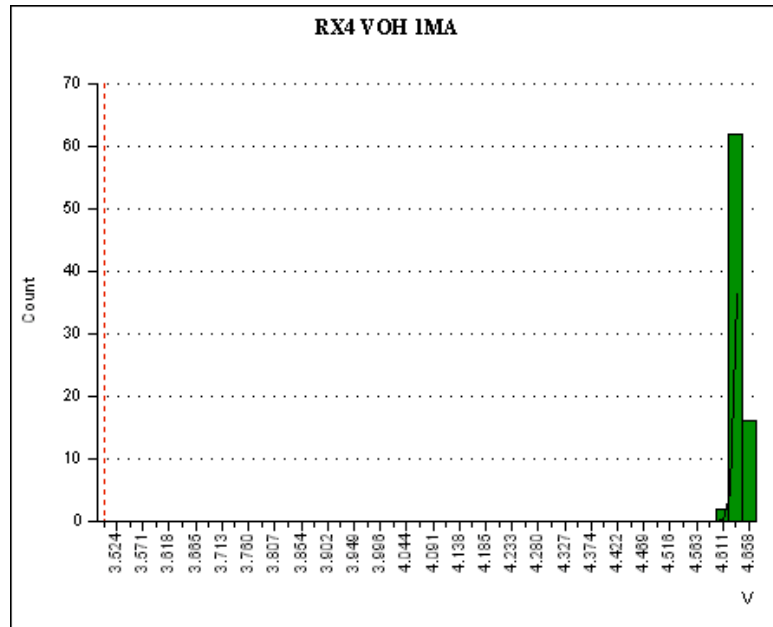
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=3.008, Test.Name=RX4 VOH 1MA



Statistics: (V)

Max	4.658	25%	4.628	SpecHigh	N/A
Mean	4.635	10%	4.625	SpecLow	3.500
Min	4.621	N	80	PctWithinSpec	100.00
Range	36.587E-03	Cp	N/A	PctDefSpec	0
StdDev	9.956E-03	Cpl	>4.0000	NWithinSpec	80
W	0.9032	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	4.651	Skew	0.7446		
75%	4.643	Kurtosis	-0.6464		
Median	4.632				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

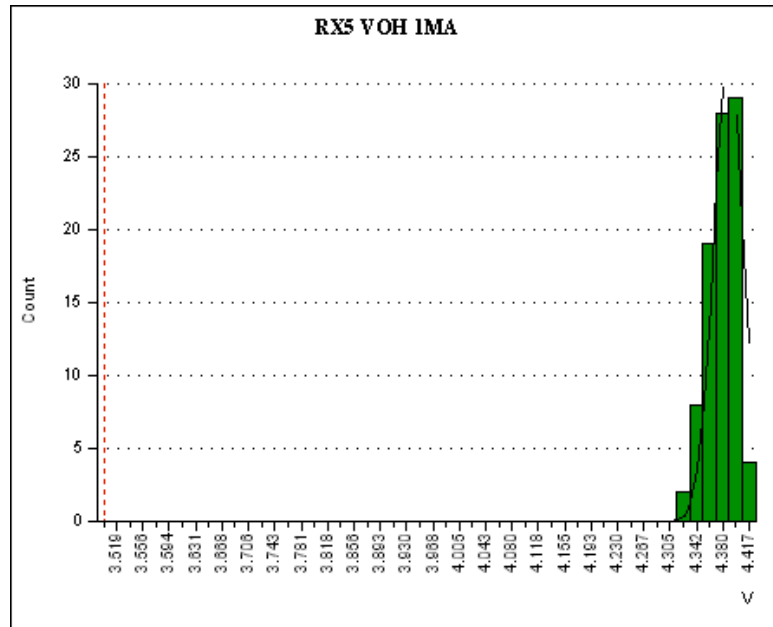
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.009, Test.Name=RX5 VOH 1MA



Statistics: (V)

Max	4.417	25%	4.359	SpecHigh	N/A
Mean	4.379	10%	4.350	SpecLow	3.500
Min	4.331	N	90	PctWithinSpec	100.00
Range	86.629E-03	Cp	N/A	PctDefSpec	0
StdDev	21.164E-03	Cpl	>4.0000	NWithinSpec	90
W	0.9513	Cpu	N/A	NOutsideSpec	0
WpValue	0.0020	Cpk	>4.0000		
90%	4.403	Skew	-0.3603		
75%	4.397	Kurtosis	-0.9265		
Median	4.381				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

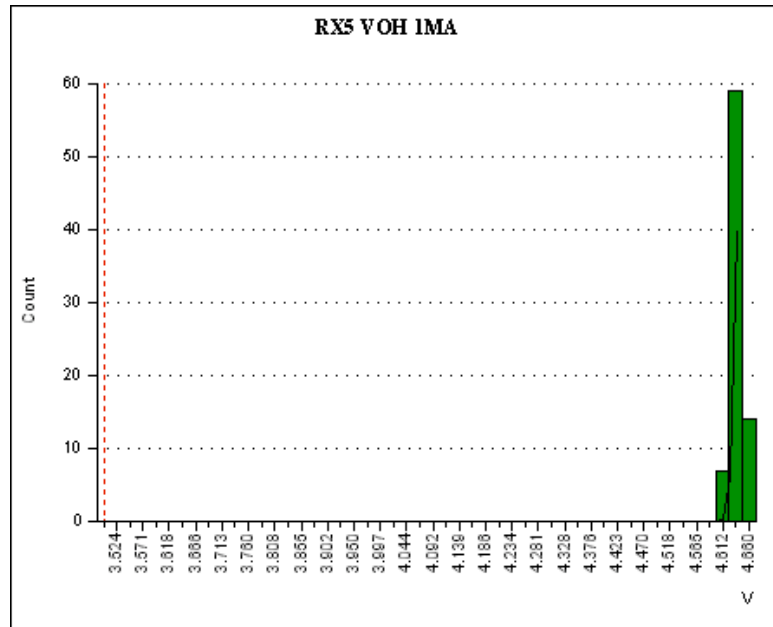
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=3.009, Test.Name=RX5 VOH 1MA



Statistics: (V)

Max	4.660	25%	4.629	SpecHigh	N/A
Mean	4.636	10%	4.625	SpecLow	3.500
Min	4.618	N	80	PctWithinSpec	100.00
Range	41.465E-03	Cp	N/A	PctDefSpec	0
StdDev	10.409E-03	Cpl	>4.0000	NWithinSpec	80
W	0.9391	Cpu	N/A	NOutsideSpec	0
WpValue	0.0009	Cpk	>4.0000		
90%	4.652	Skew	0.5052		
75%	4.646	Kurtosis	-0.7554		
Median	4.633				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

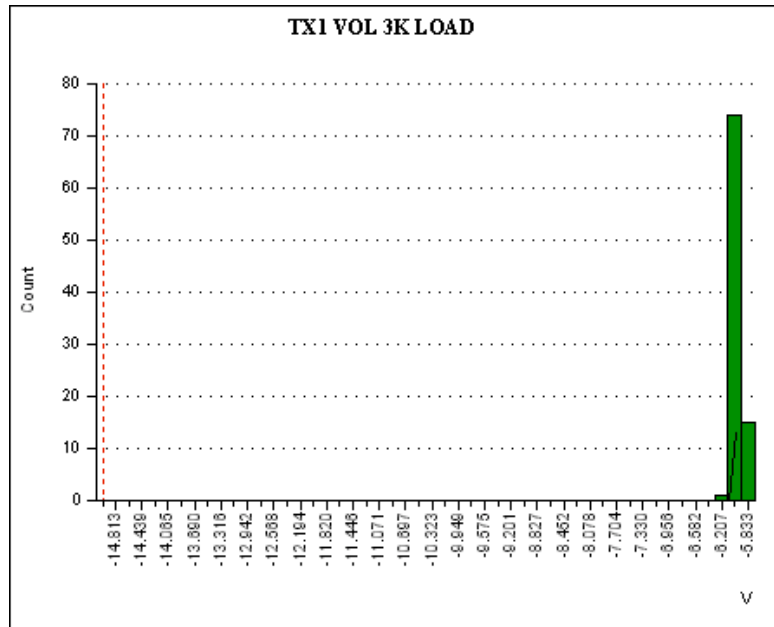
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.000, Test.Name=TX1 VOL 3K LOAD



Statistics: (V)

Max	-5.833	25%	-6.027	SpecHigh	N/A
Mean	-5.985	10%	-6.062	SpecLow	-15.000
Min	-6.125	N	90	PctWithinSpec	100.00
Range	291.410E-03	Cp	N/A	PctDefSpec	0
StdDev	58.783E-03	Cpl	>4.0000	NWithinSpec	90
W	0.9936	Cpu	N/A	NOutsideSpec	0
WpValue	0.9441	Cpk	>4.0000		
90%	-5.908	Skew	0.1674		
75%	-5.947	Kurtosis	-0.1297		
Median	-5.988				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

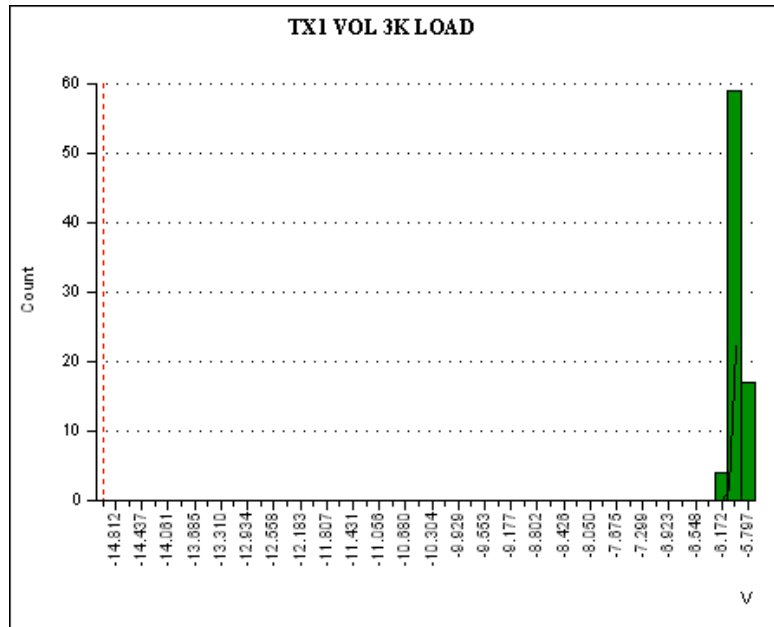
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=4.000, Test.Name=TX1 VOL 3K LOAD



Statistics: (V)

Max	-5.797	25%	-6.009	SpecHigh	N/A
Mean	-5.952	10%	-6.049	SpecLow	-15.000
Min	-6.142	N	80	PctWithinSpec	100.00
Range	345.342E-03	Cp	N/A	PctDefSpec	0
StdDev	75.662E-03	Cpl	>4.0000	NWithinSpec	80
W	0.9869	Cpu	N/A	NOutsideSpec	0
WpValue	0.5936	Cpk	>4.0000		
90%	-5.857	Skew	-0.2631		
75%	-5.897	Kurtosis	-0.4868		
Median	-5.946				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

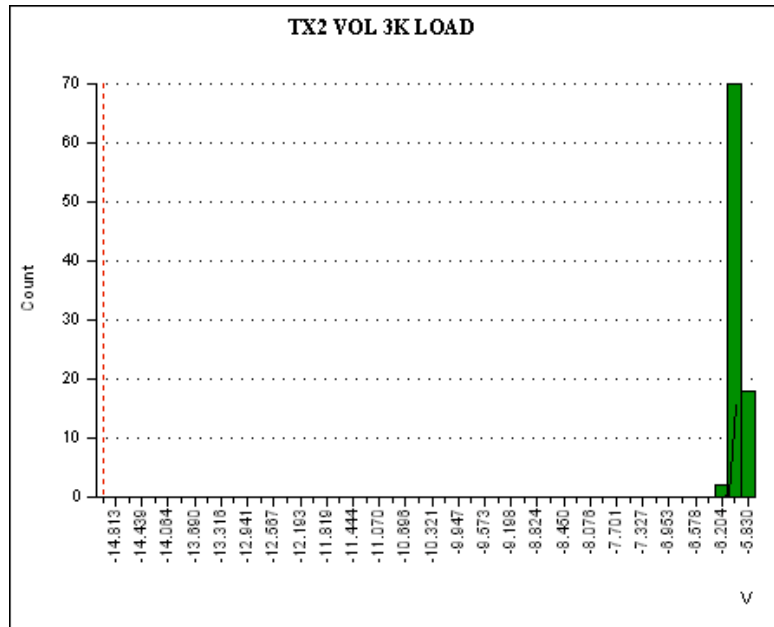
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.001, Test.Name=TX2 VOL 3K LOAD



Statistics: (V)

Max	-5.830	25%	-6.032	SpecHigh	N/A
Mean	-5.985	10%	-6.054	SpecLow	-15.000
Min	-6.120	N	90	PctWithinSpec	100.00
Range	290.117E-03	Cp	N/A	PctDefSpec	0
StdDev	60.794E-03	Cpl	>4.0000	NWithinSpec	90
W	0.9824	Cpu	N/A	NOutsideSpec	0
WpValue	0.2647	Cpk	>4.0000		
90%	-5.906	Skew	0.2202		
75%	-5.938	Kurtosis	-0.5205		
Median	-5.993				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

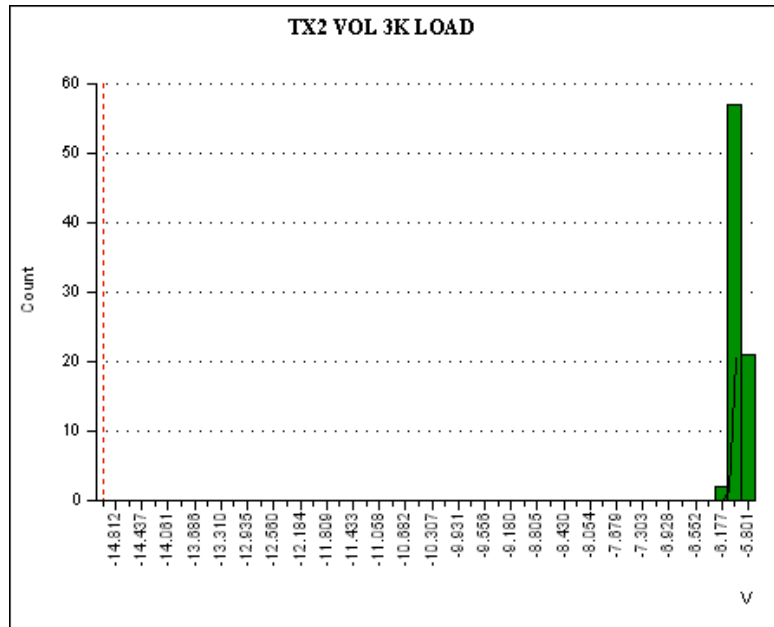
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=4.001, Test.Name=TX2 VOL 3K LOAD



Statistics: (V)

Max	-5.801	25%	-6.014	SpecHigh	N/A
Mean	-5.954	10%	-6.056	SpecLow	-15.000
Min	-6.100	N	80	PctWithinSpec	100.00
Range	298.882E-03	Cp	N/A	c	
StdDev	74.640E-03	Cpl	>4.0000	PctDefSpec	0
W	0.9761	Cpu	N/A	NWithinSpec	80
WpValue	0.1381	Cpk	>4.0000	NOutsideSpec	0
90%	-5.855	Skew	-0.0237		
75%	-5.894	Kurtosis	-0.9058		
Median	-5.956				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

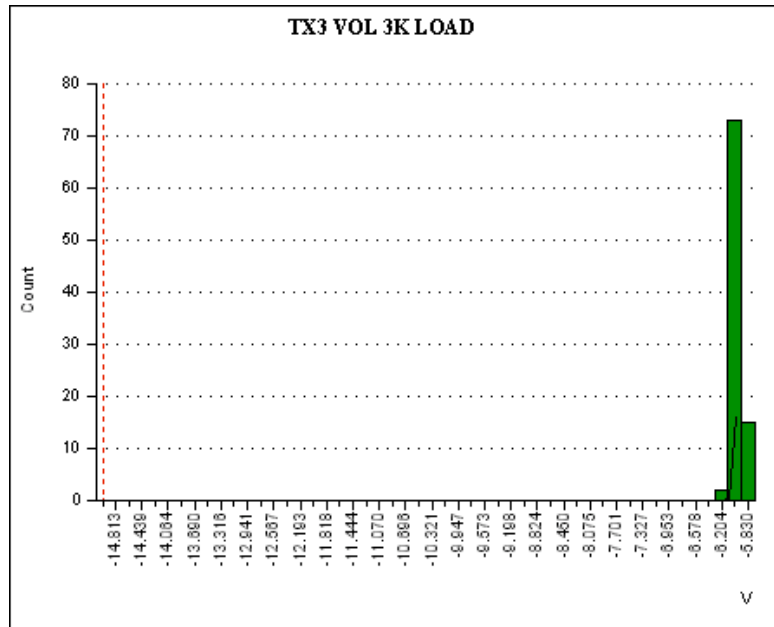
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.002, Test.Name=TX3 VOL 3K LOAD



Statistics: (V)

Max	-5.830	25%	-6.034	SpecHigh	N/A
Mean	-5.987	10%	-6.058	SpecLow	-15.000
Min	-6.123	N	90	PctWithinSpec	100.00
Range	293.162E-03	Cp	N/A	PctDefSpec	0
StdDev	59.568E-03	Cpl	>4.0000	NWithinSpec	90
W	0.9885	Cpu	N/A	NOutsideSpec	0
WpValue	0.6203	Cpk	>4.0000		
90%	-5.909	Skew	0.2070		
75%	-5.945	Kurtosis	-0.3565		
Median	-5.990				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

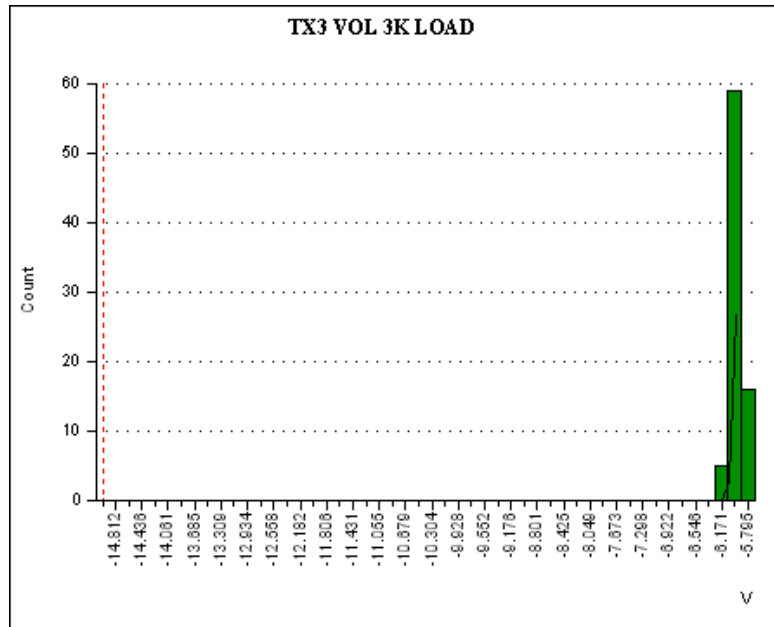
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=4.002, Test.Name=TX3 VOL 3K LOAD



Statistics: (V)

Max	-5.795	25%	-6.013	SpecHigh	N/A
Mean	-5.956	10%	-6.068	SpecLow	-15.000
Min	-6.144	N	80	PctWithinSpec	100.00
Range	349.455E-03	Cp	N/A	c	
StdDev	80.804E-03	Cpl	>4.0000	PctDefSpec	0
W	0.9880	Cpu	N/A	NWithinSpec	80
WpValue	0.6663	Cpk	>4.0000	NOutsideSpec	0
90%	-5.841	Skew	-0.0943		
75%	-5.902	Kurtosis	-0.5561		
Median	-5.953				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

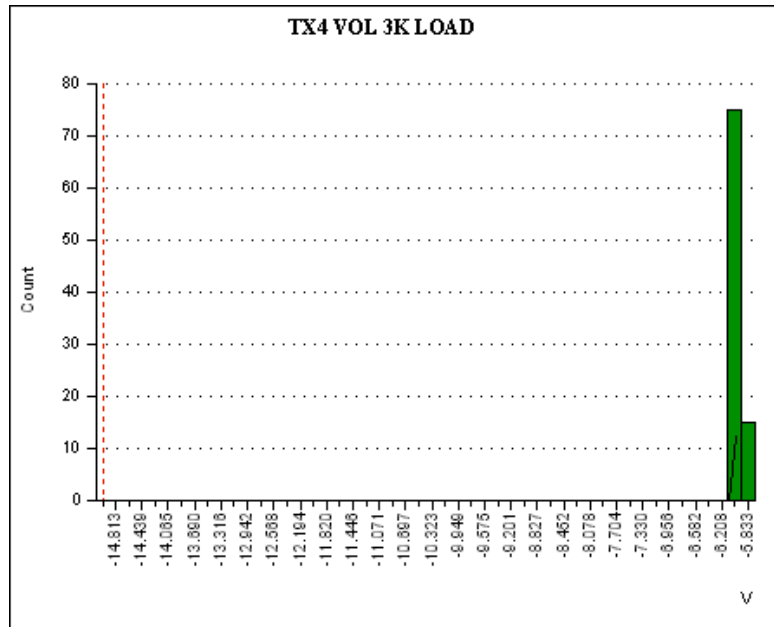
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.003, Test.Name=TX4 VOL 3K LOAD



Statistics: (V)

Max	-5.833	25%	-6.033	SpecHigh	N/A
Mean	-5.985	10%	-6.056	SpecLow	-15.000
Min	-6.108	N	90	PctWithinSpec	100.00
Range	274.197E-03	Cp	N/A	PctDefSpec	0
StdDev	58.339E-03	Cpl	>4.0000	NWithinSpec	90
W	0.9797	Cpu	N/A	NOutsideSpec	0
WpValue	0.1732	Cpk	>4.0000		
90%	-5.905	Skew	0.3277		
75%	-5.939	Kurtosis	-0.5466		
Median	-5.992				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

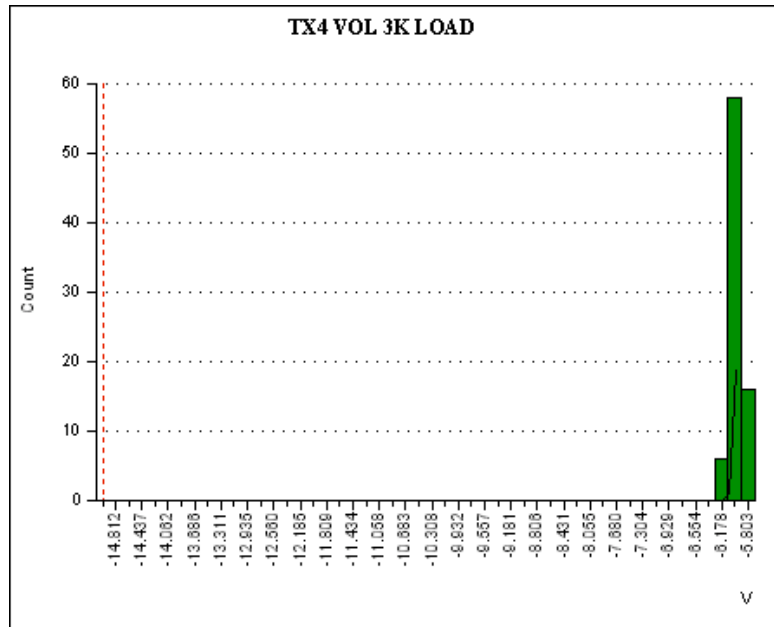
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=4.003, Test.Name=TX4 VOL 3K LOAD



Statistics: (V)

Max	-5.803	25%	-5.999	SpecHigh	N/A
Mean	-5.952	10%	-6.064	SpecLow	-15.000
Min	-6.115	N	80	PctWithinSpec	100.00
Range	311.601E-03	Cp	N/A	PctDefSpec	0
StdDev	74.425E-03	Cpl	>4.0000	NWithinSpec	80
W	0.9797	Cpu	N/A	NOutsideSpec	0
WpValue	0.2348	Cpk	>4.0000		
90%	-5.848	Skew	-0.2237		
75%	-5.903	Kurtosis	-0.2697		
Median	-5.951				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

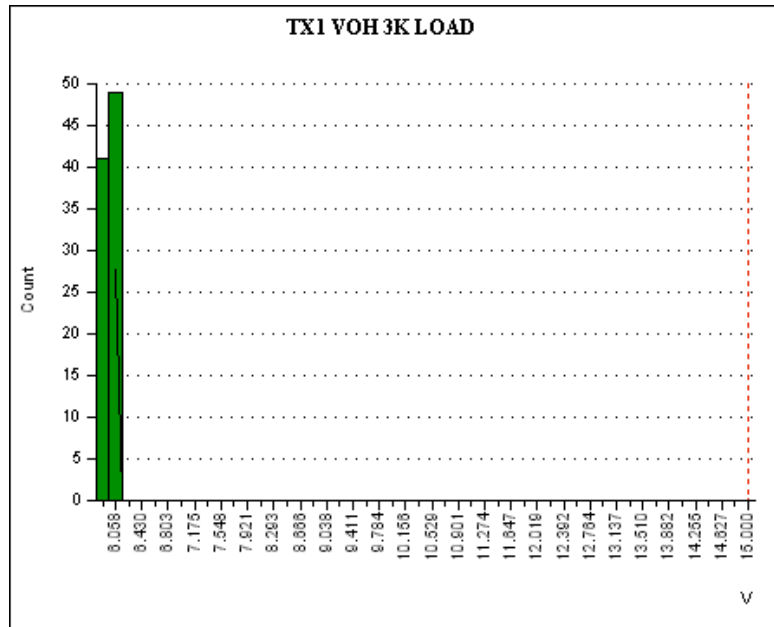
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.004, Test.Name=TX1 VOH 3K LOAD



Statistics: (V)

Max	6.088	25%	5.938	SpecHigh	15.000
Mean	5.971	10%	5.906	SpecLow	N/A
Min	5.871	N	90	PctWithinSpec	100.00
Range	216.633E-03	Cp	N/A	PctDefSpec	0
StdDev	45.641E-03	Cpl	N/A	NWithinSpec	90
W	0.9897	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.7117	Cpk	>4.0000		
90%	6.027	Skew	0.1304		
75%	6.003	Kurtosis	-0.3257		
Median	5.969				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

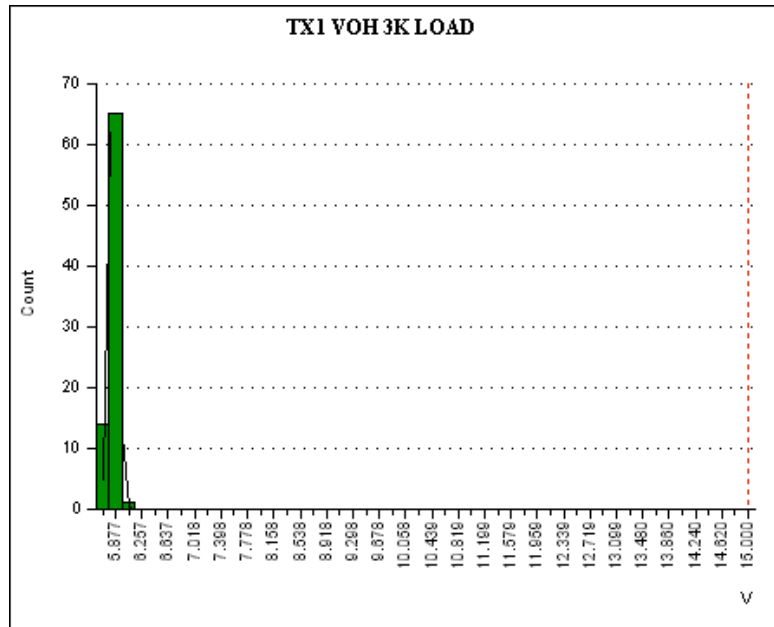
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=4.004, Test.Name=TX1 VOH 3K LOAD



Statistics: (V)

Max	6.009	25%	5.799	SpecHigh	15.000
Mean	5.840	10%	5.750	SpecLow	N/A
Min	5.687	N	80	PctWithinSpec	100.00
Range	322.033E-03	Cp	N/A	PctDefSpec	0
StdDev	62.395E-03	Cpl	N/A	NWithinSpec	80
W	0.9878	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.6523	Cpk	>4.0000		
90%	5.912	Skew	-0.1500		
75%	5.886	Kurtosis	-0.1687		
Median	5.841				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

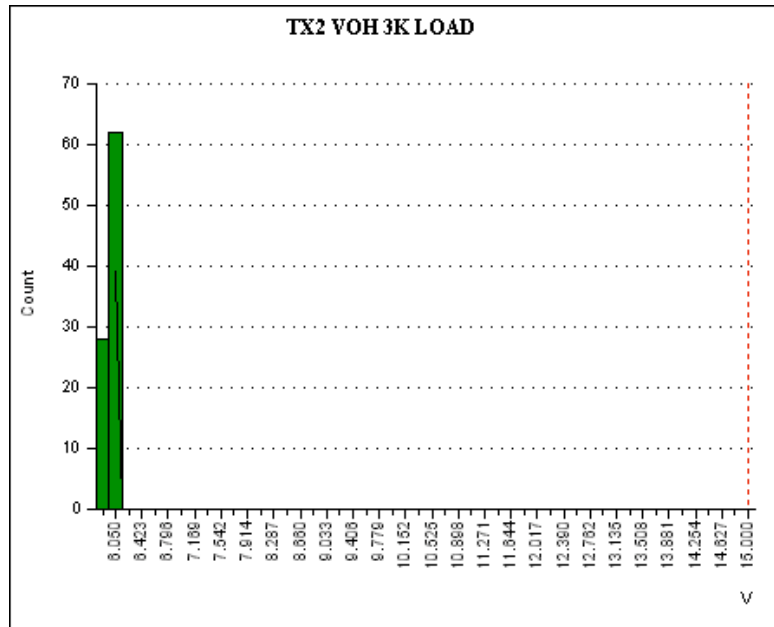
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.005, Test.Name=TX2 VOH 3K LOAD



Statistics: (V)

Max	6.078	25%	5.946	SpecHigh	15.000
Mean	5.975	10%	5.919	SpecLow	N/A
Min	5.863	N	90	PctWithinSpec	100.00
Range	214.499E-03	Cp	N/A	PctDefSpec	0
StdDev	43.081E-03	Cpl	N/A	NWithinSpec	90
W	0.9956	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.9921	Cpk	>4.0000		
90%	6.026	Skew	-0.0572		
75%	6.009	Kurtosis	-0.2535		
Median	5.975				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

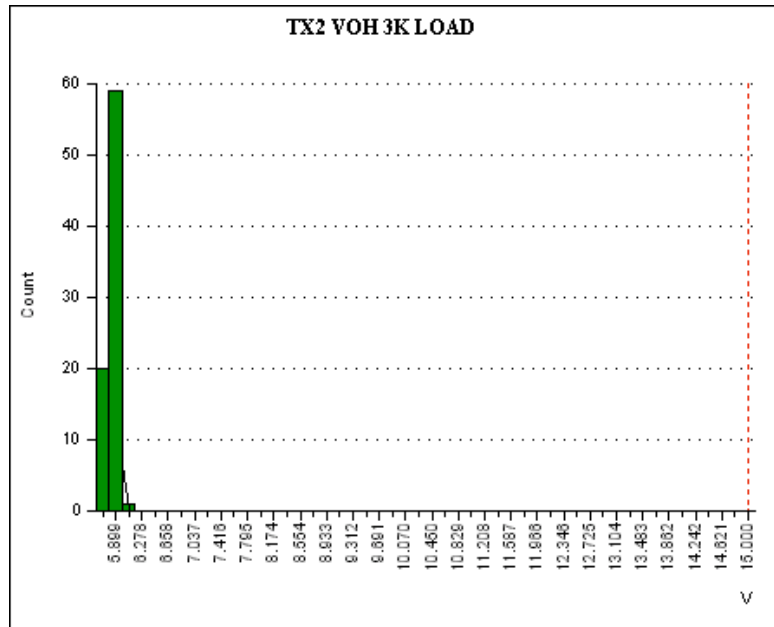
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=4.005, Test.Name=TX2 VOH 3K LOAD



Statistics: (V)

Max	6.012	25%	5.801	SpecHigh	15.000
Mean	5.843	10%	5.757	SpecLow	N/A
Min	5.710	N	80	PctWithinSpec	100.00
Range	302.765E-03	Cp	N/A	PctDefSpec	0
StdDev	62.545E-03	Cpl	N/A	NWithinSpec	80
W	0.9912	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.8631	Cpk	>4.0000		
90%	5.912	Skew	0.0042		
75%	5.883	Kurtosis	-0.1831		
Median	5.842				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

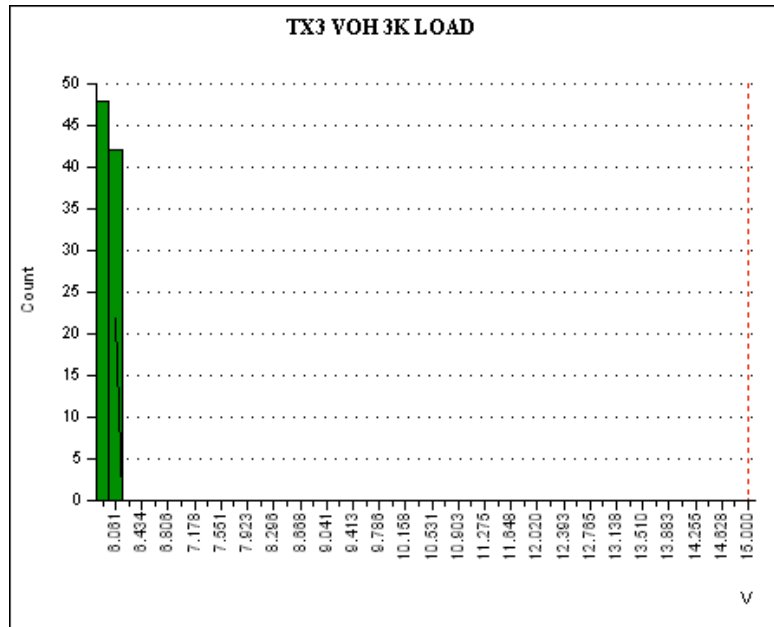
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.006, Test.Name=TX3 VOH 3K LOAD



Statistics: (V)

Max	6.081	25%	5.934	SpecHigh	15.000
Mean	5.969	10%	5.915	SpecLow	N/A
Min	5.875	N	90	PctWithinSpec	100.00
Range	205.817E-03	Cp	N/A	PctDefSpec	0
StdDev	45.236E-03	Cpl	N/A	NWithinSpec	90
W	0.9744	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0728	Cpk	>4.0000		
90%	6.031	Skew	0.3838		
75%	6.001	Kurtosis	-0.5010		
Median	5.963				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

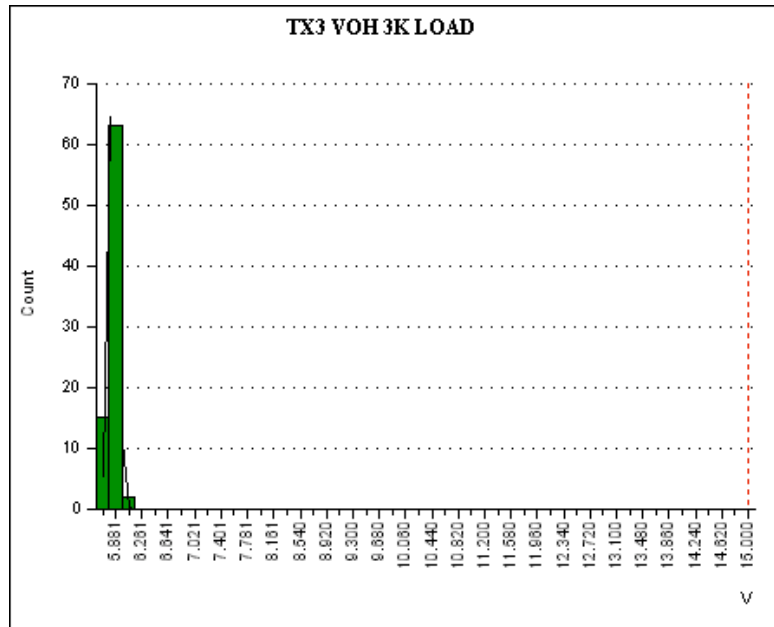
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=4.006, Test.Name=TX3 VOH 3K LOAD



Statistics: (V)

Max	5.994	25%	5.797	SpecHigh	15.000
Mean	5.840	10%	5.748	SpecLow	N/A
Min	5.691	N	80	PctWithinSpec	100.00
Range	303.527E-03	Cp	N/A	c	
StdDev	62.227E-03	Cpl	N/A	PctDefSpec	0
W	0.9886	Cpu	>4.0000	NWithinSpec	80
WpValue	0.7030	Cpk	>4.0000	NOutsideSpec	0
90%	5.912	Skew	-0.1083		
75%	5.884	Kurtosis	-0.1516		
Median	5.841				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

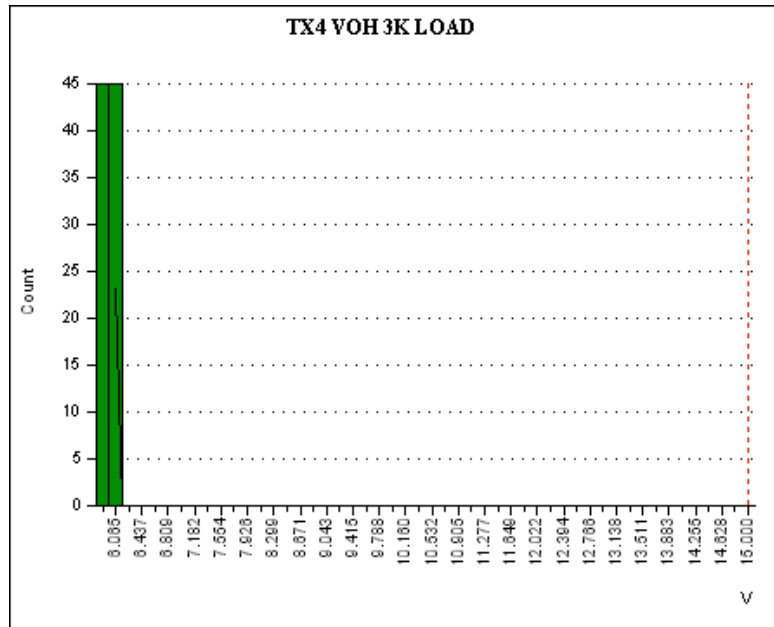
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.007, Test.Name=TX4 VOH 3K LOAD



Statistics: (V)

Max	6.091	25%	5.945	SpecHigh	15.000
Mean	5.974	10%	5.917	SpecLow	N/A
Min	5.879	N	90	PctWithinSpec	100.00
Range	212.369E-03	Cp	N/A	PctDefSpec	0
StdDev	45.053E-03	Cpl	N/A	NWithinSpec	90
W	0.9915	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.8325	Cpk	>4.0000		
90%	6.032	Skew	0.1385		
75%	6.006	Kurtosis	-0.2057		
Median	5.971				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

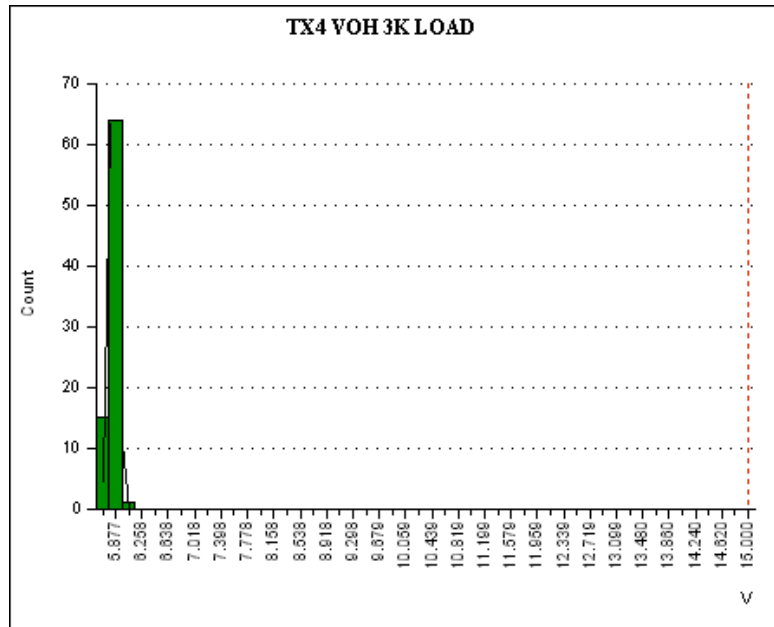
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=4.007, Test.Name=TX4 VOH 3K LOAD



Statistics: (V)

Max	5.978	25%	5.791	SpecHigh	15.000
Mean	5.838	10%	5.755	SpecLow	N/A
Min	5.687	N	80	PctWithinSpec	100.00
Range	290.349E-03	Cp	N/A	PctDefSpec	0
StdDev	60.793E-03	Cpl	N/A	NWithinSpec	80
W	0.9877	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.6452	Cpk	>4.0000		
90%	5.911	Skew	-0.1787		
75%	5.888	Kurtosis	-0.4452		
Median	5.848				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

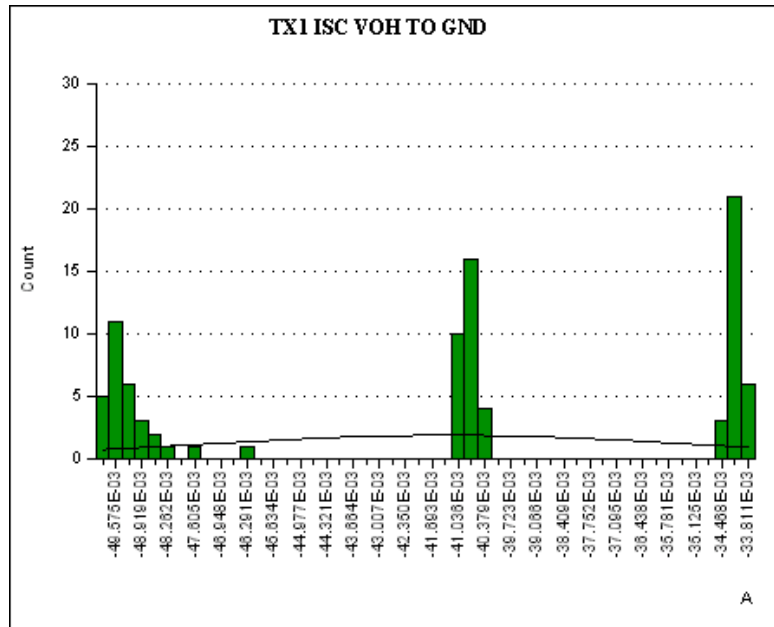
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=5.000, Test.Name=TX1 ISC VOH TO GND



Statistics: (A)

Max	-33.811E-03	25%	-48.943E-03	SpecHigh	N/A
Mean	-41.367E-03	10%	-49.546E-03	SpecLow	N/A
Min	-49.904E-03	N	90	PctWithinSpec	N/A
Range	16.093E-03	Cp	N/A	PctDefSpec	N/A
StdDev	6.222E-03	Cpl	N/A	NWithinSpec	N/A
W	0.8229	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	-34.029E-03	Skew	-0.1550		
75%	-34.215E-03	Kurtosis	-1.4908		
Median	-40.816E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

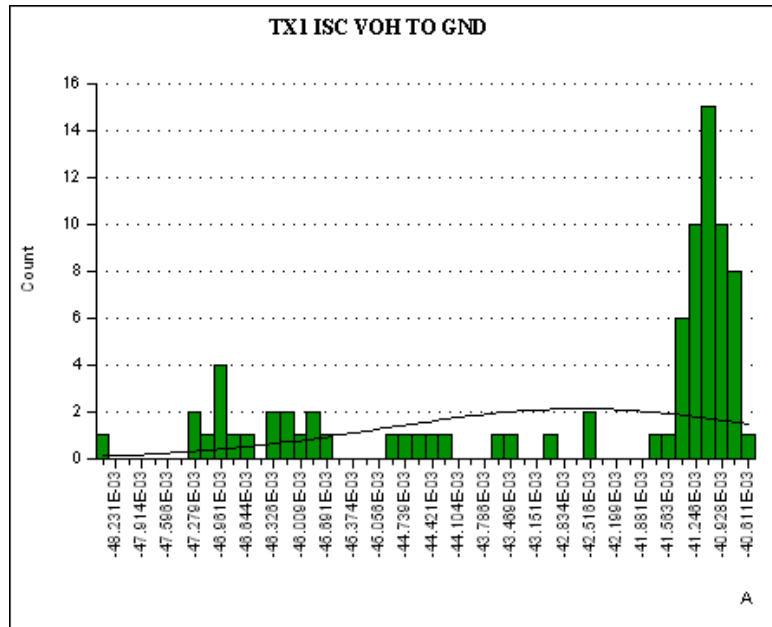
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=5.000, Test.Name=TX1 ISC VOH TO GND



Statistics: (A)

Max	-40.611E-03	25%	-44.686E-03	SpecHigh	N/A
Mean	-42.679E-03	10%	-46.804E-03	SpecLow	N/A
Min	-48.390E-03	N	80	PctWithinSpec	N/A
Range	7.779E-03	Cp	N/A	c	
StdDev	2.370E-03	Cpl	N/A	PctDefSpec	N/A
W	0.7403	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	-40.840E-03	Skew	-1.0095		
75%	-41.010E-03	Kurtosis	-0.6541		
Median	-41.249E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

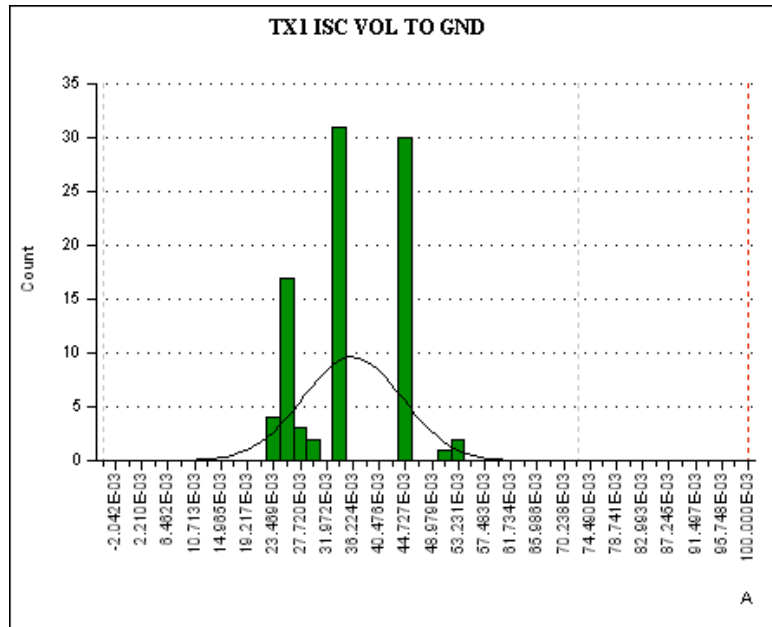
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=5.004, Test.Name=TX1 ISC VOL TO GND



Statistics: (A)

Max	53.062E-03	25%	27.240E-03	SpecHigh	100.000E-03
Mean	35.704E-03	10%	25.268E-03	SpecLow	N/A
Min	23.928E-03	N	90	PctWithinSpec	100.00
Range	29.134E-03	Cp	N/A	c	
StdDev	7.931E-03	Cpl	N/A	PctDefSpec	0
W	0.8831	Cpu	2.7024	NWithinSpec	90
WpValue	0.0000	Cpk	2.7024	NOutsideSpec	0
90%	44.303E-03	Skew	0.1594		
75%	44.073E-03	Kurtosis	-1.0908		
Median	34.157E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

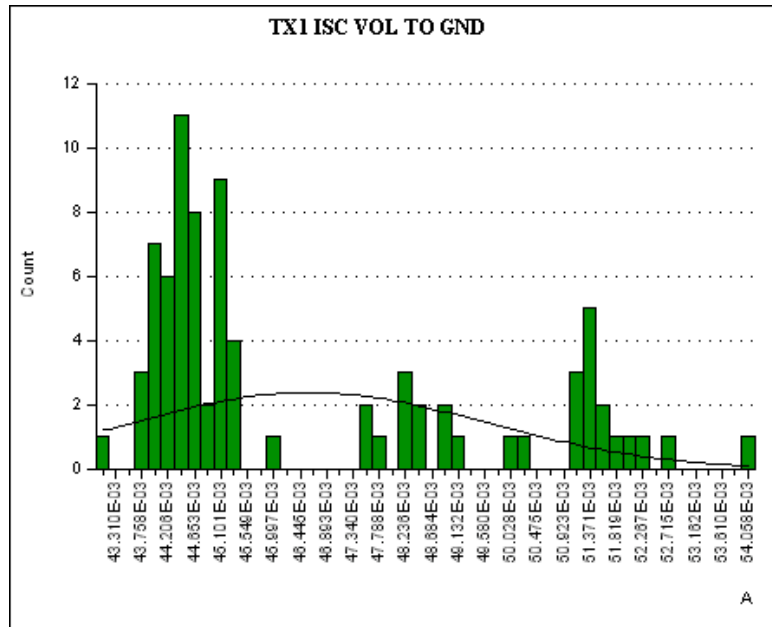
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
72.653E-03	-4.168E-03	100.00	0	90	0

Plot limits applied

NOutsidePlot
0

Test.Number=5.001, Test.Name=TX1 ISC VOL TO GND



Statistics: (A)

Max	54.058E-03	25%	44.367E-03	SpecHigh	N/A
Mean	46.558E-03	10%	44.012E-03	SpecLow	N/A
Min	43.086E-03	N	80	PctWithinSpec	N/A
Range	10.972E-03	Cp	N/A	PctDefSpec	N/A
StdDev	2.986E-03	Cpl	N/A	NWithinSpec	N/A
W	0.8059	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	51.408E-03	Skew	0.9406		
75%	48.629E-03	Kurtosis	-0.6203		
Median	45.020E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

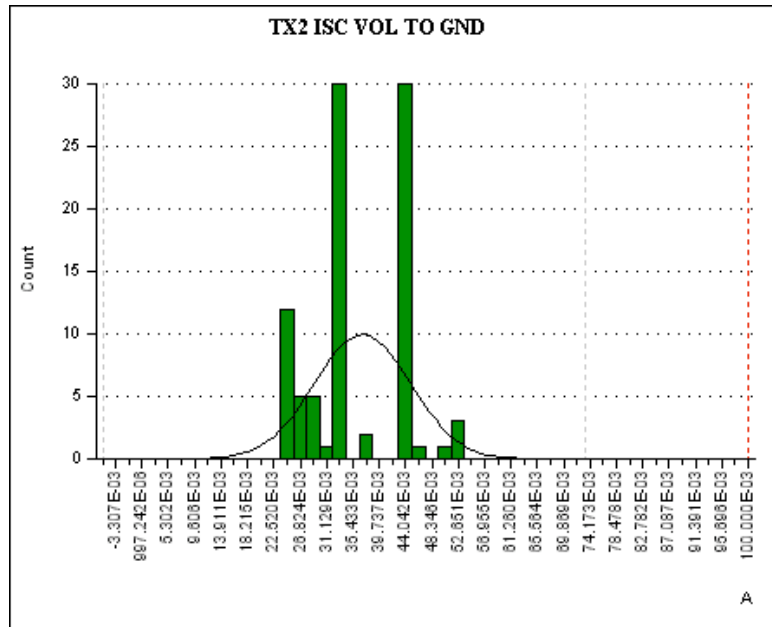
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=5.005, Test.Name=TX2 ISC VOL TO GND



Statistics: (A)

Max	53.384E-03	25%	31.923E-03	SpecHigh	100.000E-03
Mean	36.510E-03	10%	25.395E-03	SpecLow	N/A
Min	24.407E-03	N	90	PctWithinSpec	100.00
Range	28.977E-03	Cp	N/A	c	
StdDev	7.773E-03	Cpl	N/A	PctDefSpec	0
W	0.9026	Cpu	2.7227	NWithinSpec	90
WpValue	0.0000	Cpk	2.7227	NOutsideSpec	0
90%	44.282E-03	Skew	0.1065		
75%	44.065E-03	Kurtosis	-0.9993		
Median	34.144E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

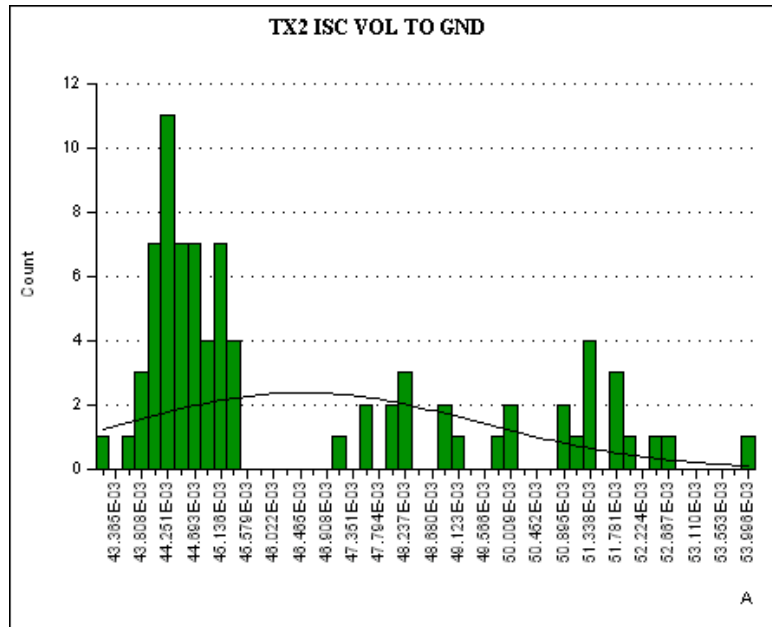
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
73.209E-03	-5.459E-03	100.00	0	90	0

Plot limits applied

NOutsidePlot
0

Test.Number=5.002, Test.Name=TX2 ISC VOL TO GND



Statistics: (A)

Max	53.996E-03	25%	44.339E-03	SpecHigh	N/A
Mean	46.485E-03	10%	43.936E-03	SpecLow	N/A
Min	43.143E-03	N	80	PctWithinSpec	N/A
Range	10.853E-03	Cp	N/A	PctDefSpec	N/A
StdDev	2.959E-03	Cpl	N/A	NWithinSpec	N/A
W	0.8050	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	51.382E-03	Skew	0.9691		
75%	48.529E-03	Kurtosis	-0.5476		
Median	44.960E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

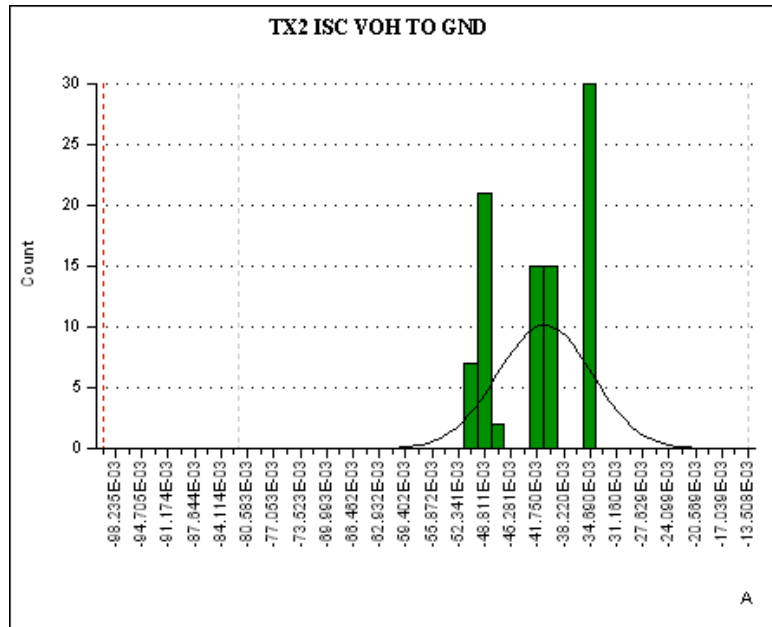
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=5.001, Test.Name=TX2 ISC VOH TO GND



Statistics: (A)

Max	-33.841E-03	25%	-48.900E-03	SpecHigh	N/A
Mean	-41.397E-03	10%	-49.521E-03	SpecLow	-100.000E-03
Min	-49.947E-03	N	90	PctWithinSpec	100.00
Range	16.106E-03	Cp	N/A	PctDefSpec	0
StdDev	6.206E-03	Cpl	3.1477	NWithinSpec	90
W	0.8247	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	3.1477		
90%	-34.058E-03	Skew	-0.1512		
75%	-34.265E-03	Kurtosis	-1.4895		
Median	-40.858E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

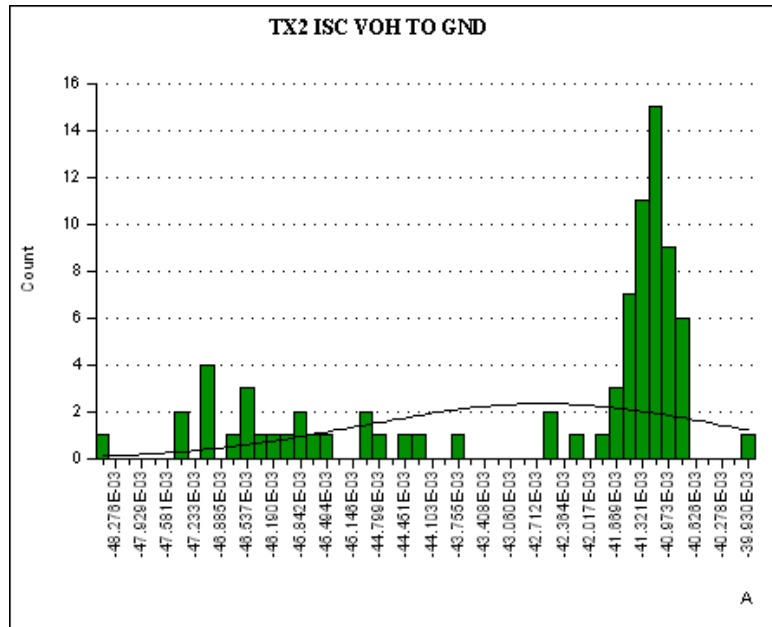
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
-13.508E-03	-81.745E-03	100.00	0	90	0

Plot limits applied

NOutsidePlot
0

Test.Number=5.003, Test.Name=TX2 ISC VOH TO GND



Statistics: (A)

Max	-39.930E-03	25%	-44.859E-03	SpecHigh	N/A
Mean	-42.688E-03	10%	-46.693E-03	SpecLow	N/A
Min	-48.450E-03	N	80	PctWithinSpec	N/A
Range	8.520E-03	Cp	N/A	PctDefSpec	N/A
StdDev	2.352E-03	Cpl	N/A	NWithinSpec	N/A
W	0.7507	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	-40.901E-03	Skew	-1.0351		
75%	-41.073E-03	Kurtosis	-0.5786		
Median	-41.344E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

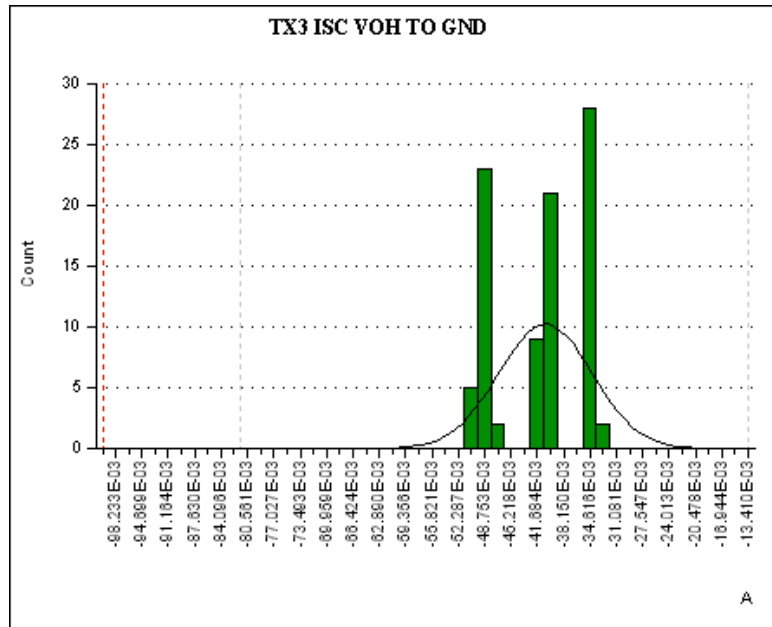
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=5.002, Test.Name=TX3 ISC VOH TO GND



Statistics: (A)

Max	-33.621E-03	25%	-48.837E-03	SpecHigh	N/A
Mean	-41.252E-03	10%	-49.399E-03	SpecLow	-100.000E-03
Min	-49.781E-03	N	90	PctWithinSpec	100.00
Range	16.160E-03	Cp	N/A	PctDefSpec	0
StdDev	6.197E-03	Cpl	3.1598	NWithinSpec	90
W	0.8243	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	3.1598		
90%	-33.938E-03	Skew	-0.1539		
75%	-34.118E-03	Kurtosis	-1.4903		
Median	-40.714E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

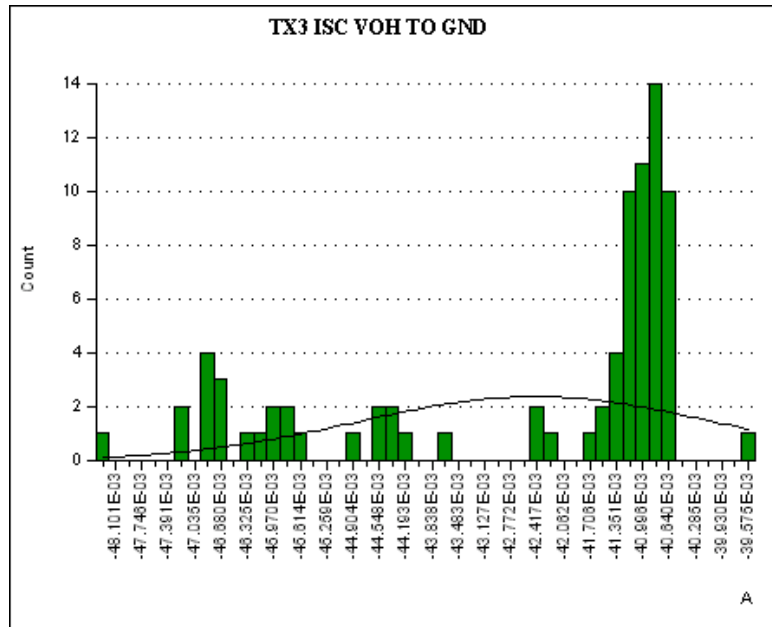
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
-13.410E-03	-81.501E-03	100.00	0	90	0

Plot limits applied

NOutsidePlot
0

Test.Number=5.004, Test.Name=TX3 ISC VOH TO GND



Statistics: (A)

Max	-39.575E-03	25%	-44.462E-03	SpecHigh	N/A
Mean	-42.495E-03	10%	-46.697E-03	SpecLow	N/A
Min	-48.279E-03	N	80	PctWithinSpec	N/A
Range	8.704E-03	Cp	N/A	c	
StdDev	2.377E-03	Cpl	N/A	PctDefSpec	N/A
W	0.7481	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	-40.713E-03	Skew	-1.0392		
75%	-40.868E-03	Kurtosis	-0.5620		
Median	-41.107E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

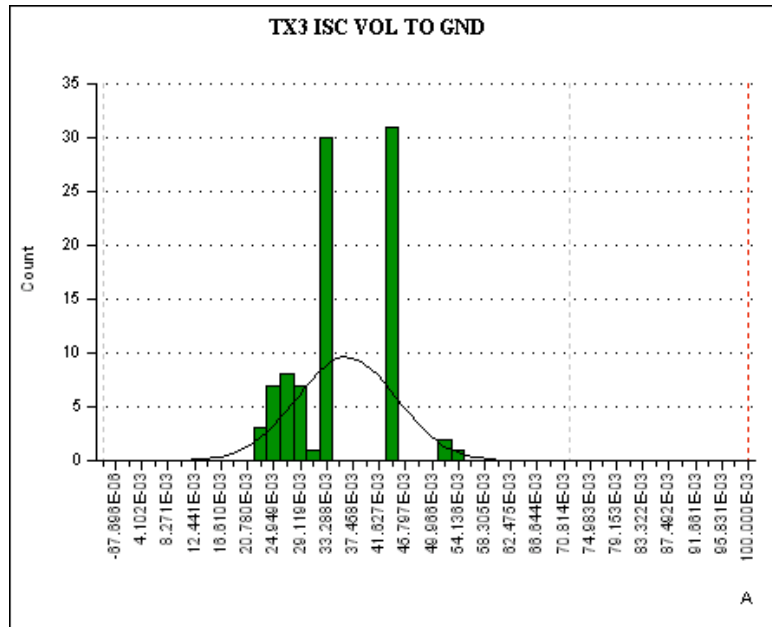
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=5.006, Test.Name=TX3 ISC VOL TO GND



Statistics: (A)

Max	53.103E-03	25%	29.263E-03	SpecHigh	100.000E-03
Mean	36.035E-03	10%	25.553E-03	SpecLow	N/A
Min	22.276E-03	N	90	PctWithinSpec	100.00
Range	30.827E-03	Cp	N/A	PctDefSpec	0
StdDev	7.778E-03	Cpl	N/A	NWithinSpec	90
W	0.9001	Cpu	2.7415	NOutsideSpec	0
WpValue	0.0000	Cpk	2.7415		
90%	44.332E-03	Skew	0.1420		
75%	44.089E-03	Kurtosis	-1.0365		
Median	34.104E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

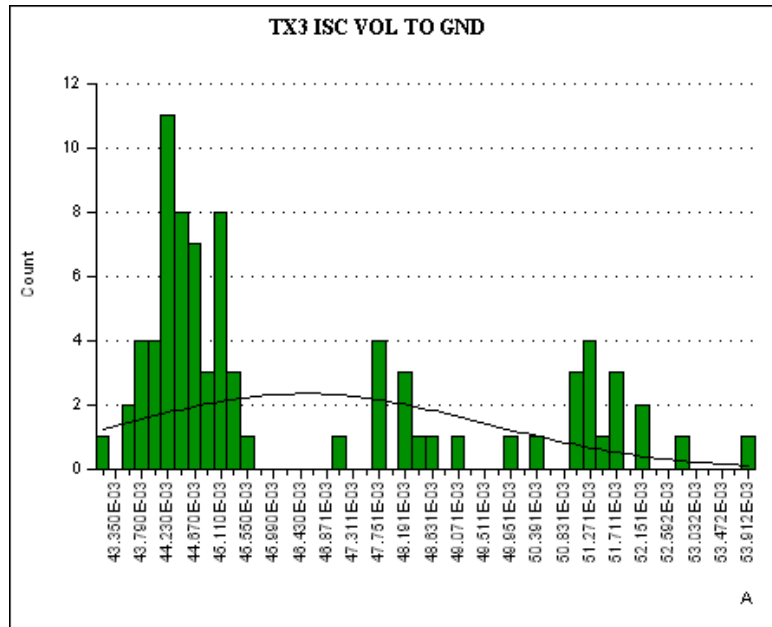
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
71.642E-03	-2.152E-03	100.00	0	90	0

Plot limits applied

NOutsidePlot
0

Test.Number=5.005, Test.Name=TX3 ISC VOL TO GND



Statistics: (A)

Max	53.912E-03	25%	44.311E-03	SpecHigh	N/A
Mean	46.479E-03	10%	43.986E-03	SpecLow	N/A
Min	43.130E-03	N	80	PctWithinSpec	N/A
Range	10.782E-03	Cp	N/A	PctDefSpec	N/A
StdDev	2.979E-03	Cpl	N/A	NWithinSpec	N/A
W	0.8005	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	51.364E-03	Skew	0.9729		
75%	48.310E-03	Kurtosis	-0.5693		
Median	44.993E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

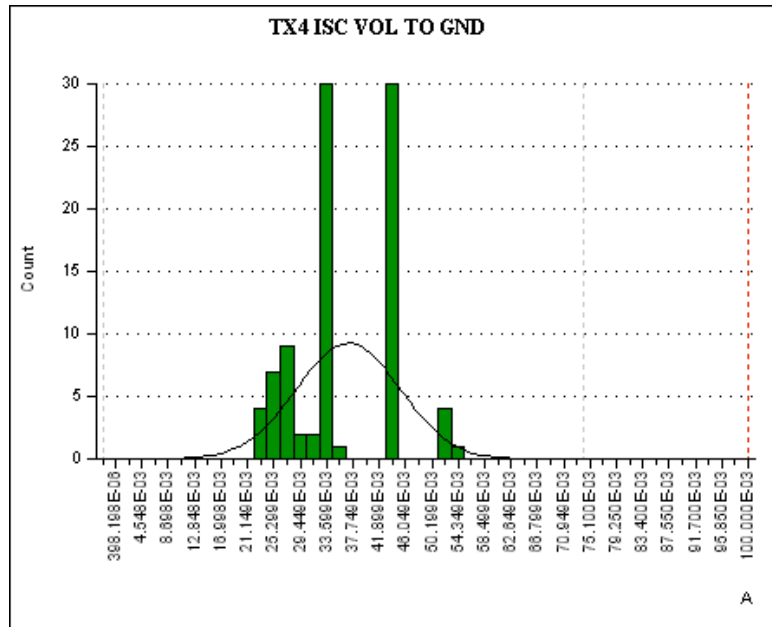
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=5.007, Test.Name=TX4 ISC VOL TO GND



Statistics: (A)

Max	53.564E-03	25%	31.183E-03	SpecHigh	100.000E-03
Mean	36.571E-03	10%	25.803E-03	SpecLow	N/A
Min	23.038E-03	N	90	PctWithinSpec	100.00
Range	30.526E-03	Cp	N/A	PctDefSpec	0
StdDev	8.045E-03	Cpl	N/A	NWithinSpec	90
W	0.9086	Cpu	2.6280	NOutsideSpec	0
WpValue	0.0000	Cpk	2.6280		
90%	44.431E-03	Skew	0.1826		
75%	44.232E-03	Kurtosis	-0.8822		
Median	34.208E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

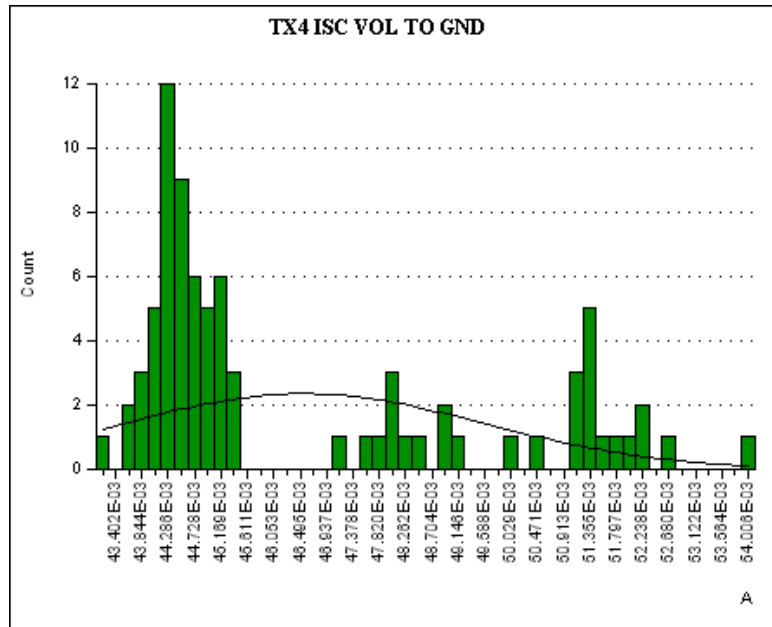
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
73.968E-03	-1.677E-03	100.00	0	90	0

Plot limits applied

NOutsidePlot
0

Test.Number=5.006, Test.Name=TX4 ISC VOL TO GND



Statistics: (A)

Max	54.006E-03	25%	44.354E-03	SpecHigh	N/A
Mean	46.527E-03	10%	44.023E-03	SpecLow	N/A
Min	43.181E-03	N	80	PctWithinSpec	N/A
Range	10.825E-03	Cp	N/A	PctDefSpec	N/A
StdDev	2.991E-03	Cpl	N/A	NWithinSpec	N/A
W	0.7975	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	51.344E-03	Skew	0.9663		
75%	48.627E-03	Kurtosis	-0.5906		
Median	44.955E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

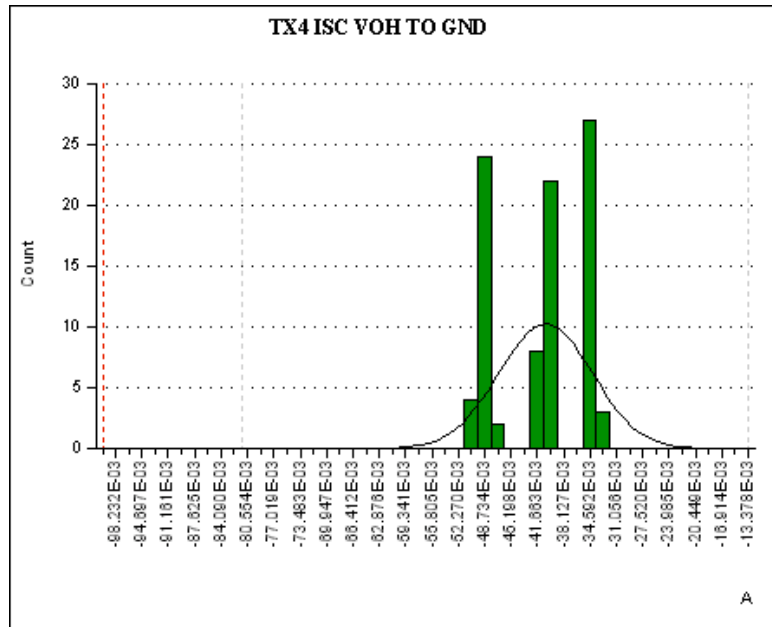
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=5.003, Test.Name=TX4 ISC VOH TO GND



Statistics: (A)

Max	-33.643E-03	25%	-48.862E-03	SpecHigh	N/A
Mean	-41.200E-03	10%	-49.369E-03	SpecLow	-100.000E-03
Min	-49.711E-03	N	90	PctWithinSpec	100.00
Range	16.068E-03	Cp	N/A	PctDefSpec	0
StdDev	6.202E-03	Cpl	3.1600	NWithinSpec	90
W	0.8238	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	3.1600		
90%	-33.910E-03	Skew	-0.1582		
75%	-34.070E-03	Kurtosis	-1.4904		
Median	-40.631E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

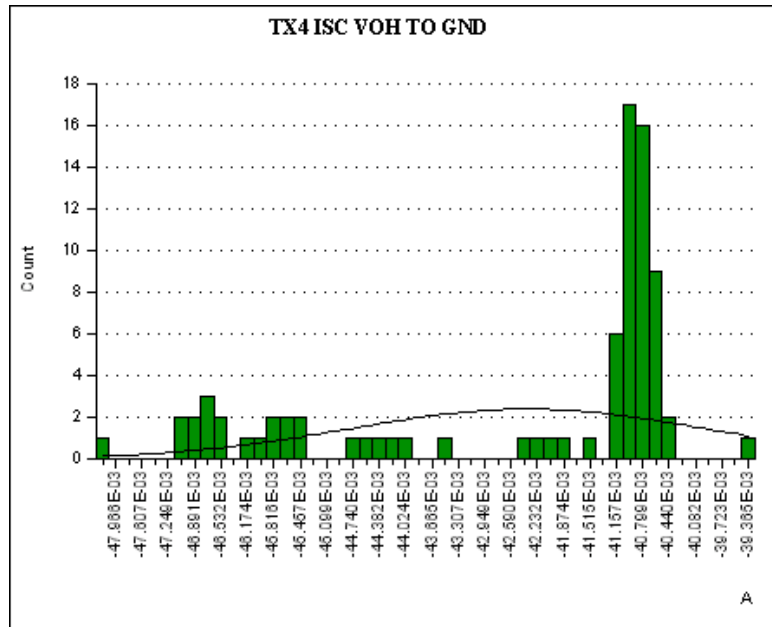
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
-13.378E-03	-81.390E-03	100.00	0	90	0

Plot limits applied

NOutsidePlot
0

Test.Number=5.007, Test.Name=TX4 ISC VOH TO GND



Statistics: (A)

Max	-39.365E-03	25%	-44.539E-03	SpecHigh	N/A
Mean	-42.419E-03	10%	-46.651E-03	SpecLow	N/A
Min	-48.145E-03	N	80	PctWithinSpec	N/A
Range	8.780E-03	Cp	N/A	c	
StdDev	2.389E-03	Cpl	N/A	PctDefSpec	N/A
W	0.7451	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	-40.646E-03	Skew	-1.0196		
75%	-40.813E-03	Kurtosis	-0.6180		
Median	-41.004E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

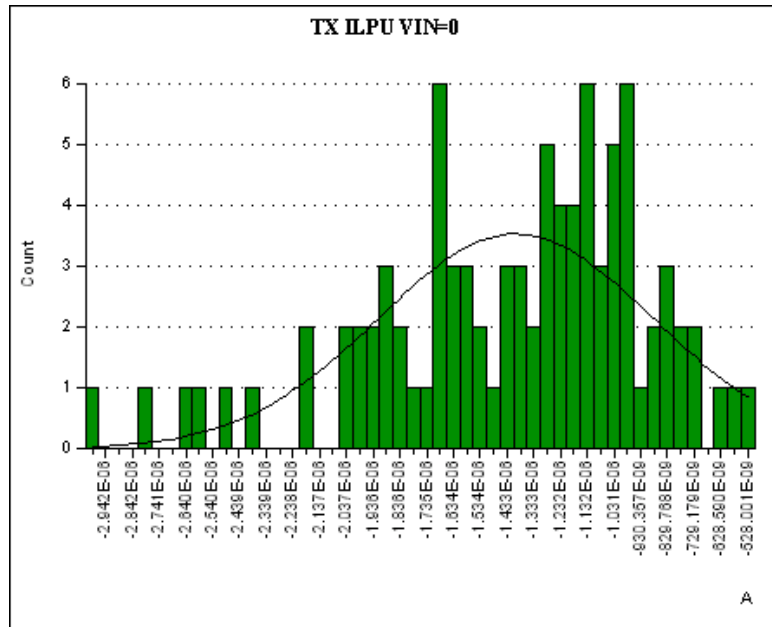
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=6.000, Test.Name=TX ILPU VIN=0



Statistics: (A)

Max	-528.001E-09	25%	-1.683E-06	SpecHigh	N/A
Mean	-1.418E-06	10%	-2.023E-06	SpecLow	N/A
Min	-2.992E-06	N	90	PctWithinSpec	N/A
Range	2.464E-06	Cp	N/A	PctDefSpec	N/A
StdDev	511.247E-09	Cpl	N/A	NWithinSpec	N/A
W	0.9534	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0027	Cpk	N/A		
90%	-826.556E-09	Skew	-0.8261		
75%	-1.045E-06	Kurtosis	0.5724		
Median	-1.300E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

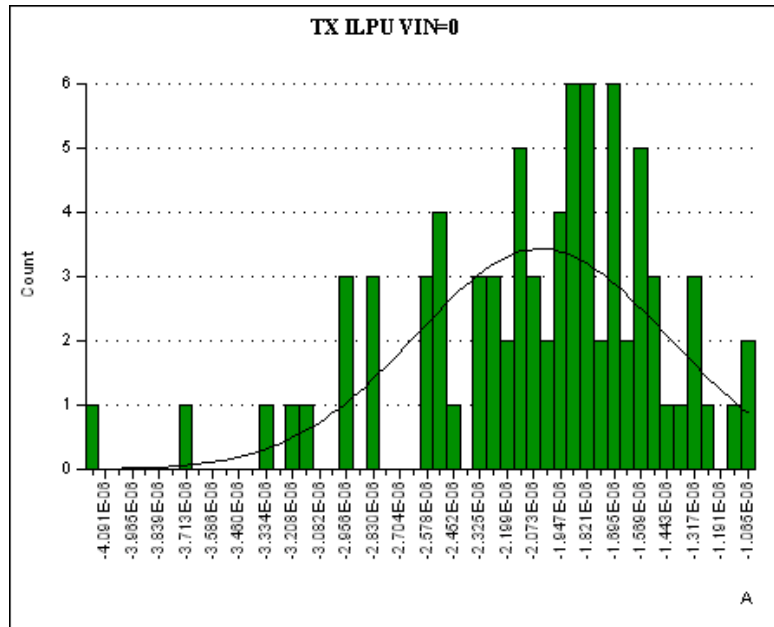
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=6.000, Test.Name=TX ILPU VIN=0



Statistics: (A)

Max	-1.065E-06	25%	-2.326E-06	SpecHigh	N/A
Mean	-2.063E-06	10%	-2.891E-06	SpecLow	N/A
Min	-4.154E-06	N	80	PctWithinSpec	N/A
Range	3.089E-06	Cp	N/A	PctDefSpec	N/A
StdDev	586.664E-09	Cpl	N/A	NWithinSpec	N/A
W	0.9421	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0012	Cpk	N/A		
90%	-1.428E-06	Skew	-1.0278		
75%	-1.675E-06	Kurtosis	1.5329		
Median	-1.925E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

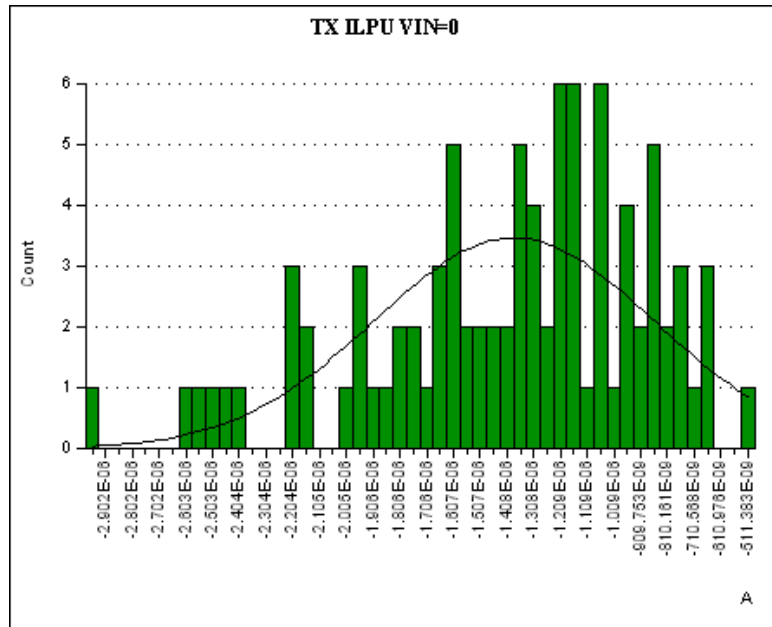
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=6.001, Test.Name=TX ILPU VIN=0



Statistics: (A)

Max	-511.383E-09	25%	-1.675E-06	SpecHigh	N/A
Mean	-1.399E-06	10%	-2.180E-06	SpecLow	N/A
Min	-2.951E-06	N	90	PctWithinSpec	N/A
Range	2.440E-06	Cp	N/A	c	
StdDev	515.915E-09	Cpl	N/A	PctDefSpec	N/A
W	0.9548	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0034	Cpk	N/A	NOutsideSpec	N/A
90%	-813.308E-09	Skew	-0.7588		
75%	-1.035E-06	Kurtosis	0.1924		
Median	-1.300E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

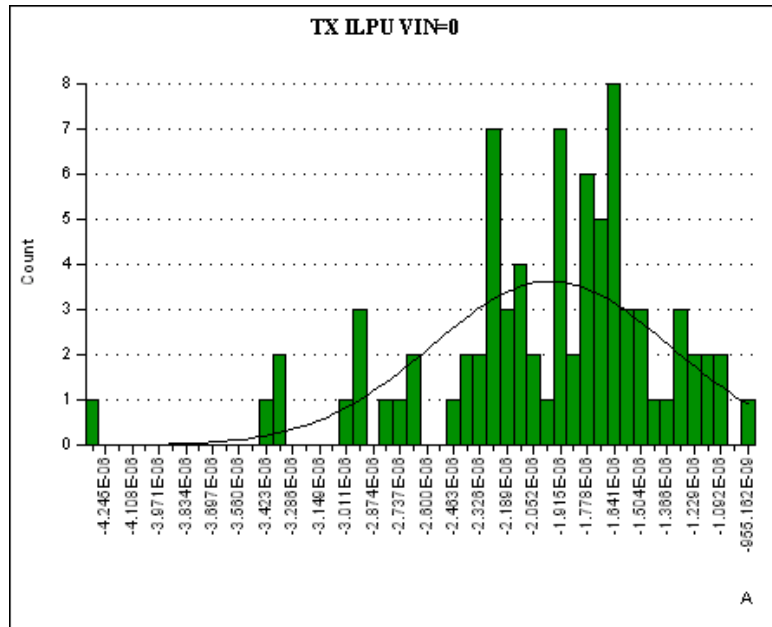
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=6.001, Test.Name=TX ILPU VIN=0



Statistics: (A)

Max	-955.162E-09	25%	-2.264E-06	SpecHigh	N/A
Mean	-1.991E-06	10%	-2.866E-06	SpecLow	N/A
Min	-4.314E-06	N	80	PctWithinSpec	N/A
Range	3.359E-06	Cp	N/A	PctDefSpec	N/A
StdDev	603.305E-09	Cpl	N/A	NWithinSpec	N/A
W	0.9308	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0003	Cpk	N/A		
90%	-1.286E-06	Skew	-1.1348		
75%	-1.625E-06	Kurtosis	2.0672		
Median	-1.900E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

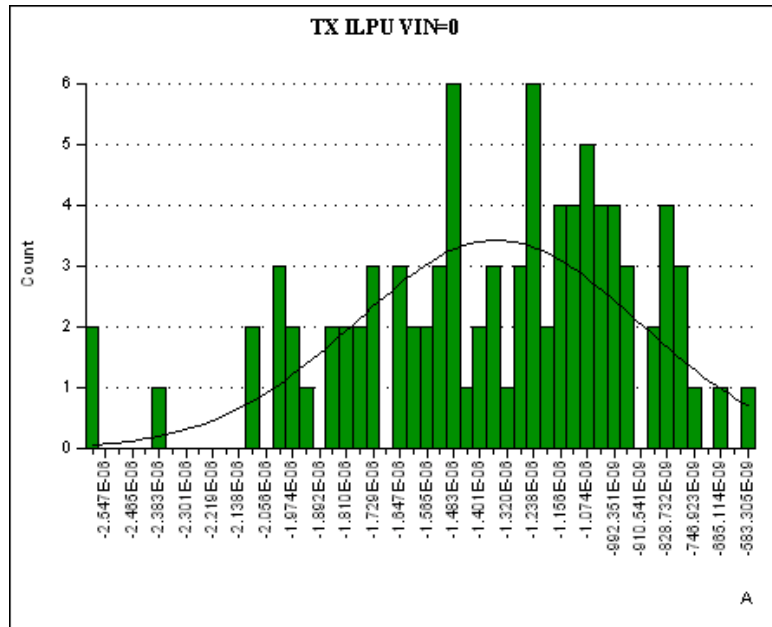
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=6.002, Test.Name=TX ILPU VIN=0



Statistics: (A)

Max	-583.305E-09	25%	-1.636E-06	SpecHigh	N/A
Mean	-1.363E-06	10%	-1.983E-06	SpecLow	N/A
Min	-2.588E-06	N	90	PctWithinSpec	N/A
Range	2.004E-06	Cp	N/A	c	
StdDev	428.561E-09	Cpl	N/A	PctDefSpec	N/A
W	0.9634	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0124	Cpk	N/A	NOutsideSpec	N/A
90%	-825.796E-09	Skew	-0.6680		
75%	-1.052E-06	Kurtosis	0.1701		
Median	-1.266E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

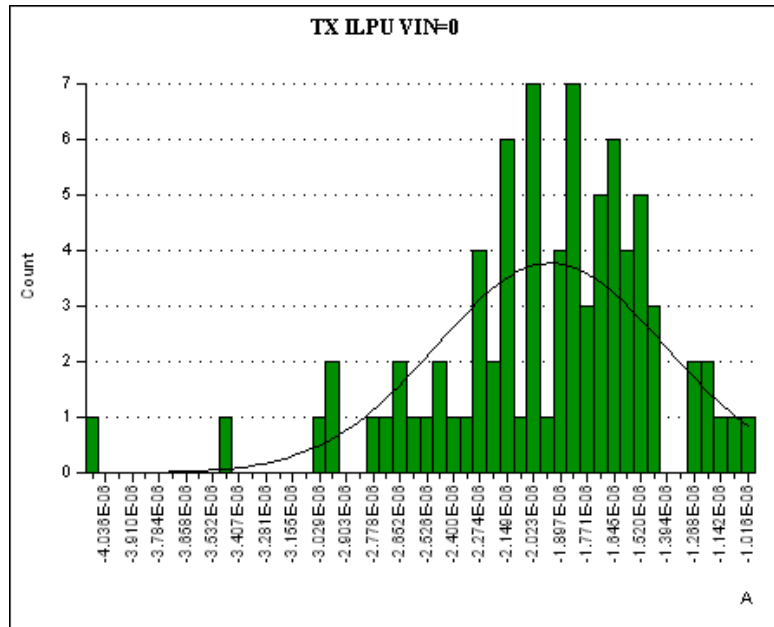
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=6.002, Test.Name=TX ILPU VIN=0



Statistics: (A)

Max	-1.016E-06	25%	-2.225E-06	SpecHigh	N/A
Mean	-1.968E-06	10%	-2.645E-06	SpecLow	N/A
Min	-4.099E-06	N	80	PctWithinSpec	N/A
Range	3.082E-06	Cp	N/A	PctDefSpec	N/A
StdDev	532.021E-09	Cpl	N/A	NWithinSpec	N/A
W	0.9348	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0005	Cpk	N/A		
90%	-1.471E-06	Skew	-1.1645		
75%	-1.625E-06	Kurtosis	2.6857		
Median	-1.873E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

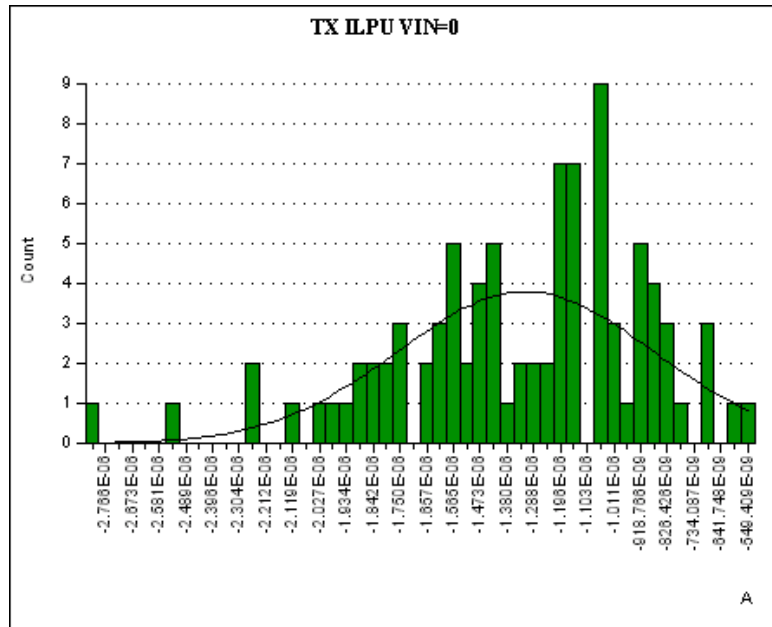
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=6.003, Test.Name=TX ILPU VIN=0



Statistics: (A)

Max	-549.409E-09	25%	-1.585E-06	SpecHigh	N/A
Mean	-1.332E-06	10%	-1.877E-06	SpecLow	N/A
Min	-2.812E-06	N	90	PctWithinSpec	N/A
Range	2.262E-06	Cp	N/A	PctDefSpec	N/A
StdDev	436.240E-09	Cpl	N/A	NWithinSpec	N/A
W	0.9602	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0075	Cpk	N/A		
90%	-851.367E-09	Skew	-0.8066		
75%	-1.040E-06	Kurtosis	0.7984		
Median	-1.227E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

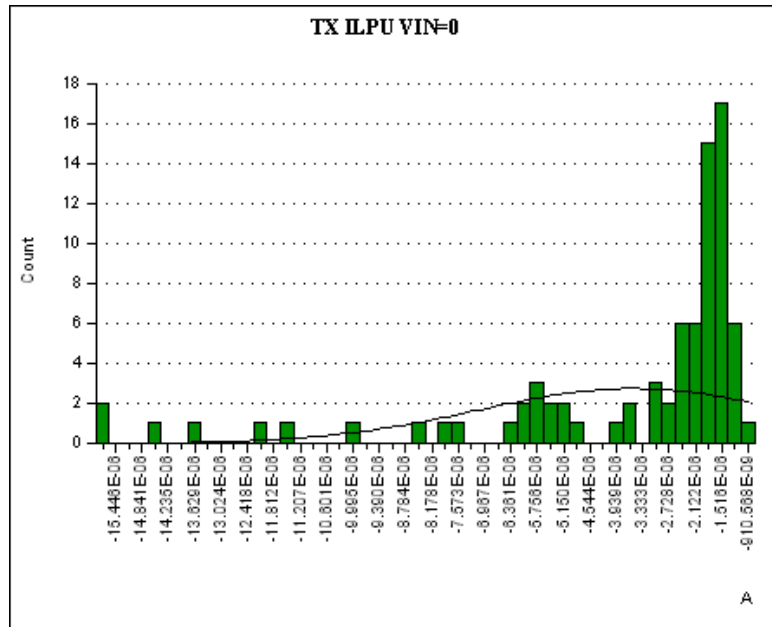
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=6.003, Test.Name=TX ILPU VIN=0



Statistics: (A)

Max	-910.568E-09	25%	-5.088E-06	SpecHigh	N/A
Mean	-3.678E-06	10%	-8.106E-06	SpecLow	N/A
Min	-15.749E-06	N	80	PctWithinSpec	N/A
Range	14.839E-06	Cp	N/A	c	
StdDev	3.522E-06	Cpl	N/A	PctDefSpec	N/A
W	0.6841	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	-1.443E-06	Skew	-2.0792		
75%	-1.630E-06	Kurtosis	3.7888		
Median	-2.005E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

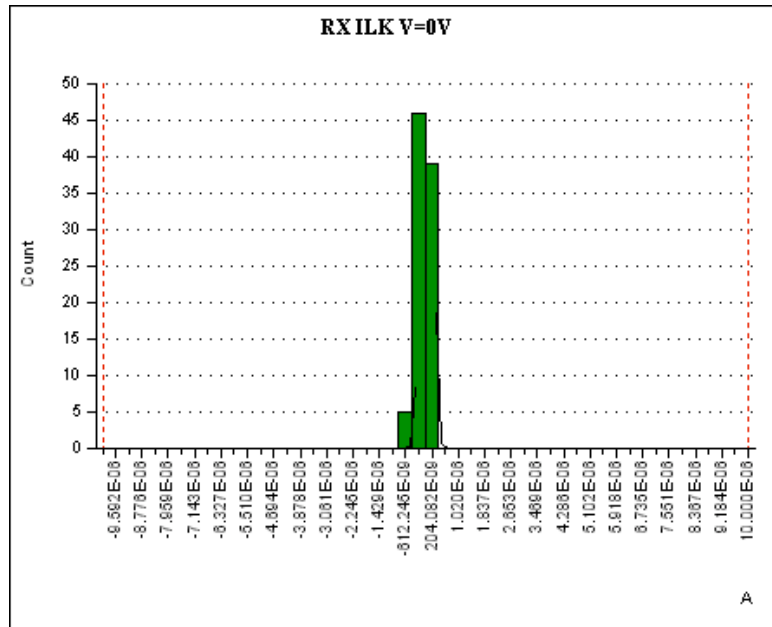
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=7.000, Test.Name=RX ILK V=0V



Statistics: (A)

Max	32.307E-09	25%	-64.424E-09	SpecHigh	10.000E-06
Mean	-70.786E-09	10%	-290.989E-09	SpecLow	-10.000E-06
Min	-645.852E-09	N	90	PctWithinSpec	100.00
Range	678.159E-09	Cp	>4.0000	PctDefSpec	0
StdDev	147.649E-09	Cpl	>4.0000	NWithinSpec	90
W	0.6271	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	13.501E-09	Skew	-2.1965		
75%	8.380E-09	Kurtosis	4.1683		
Median	-3.463E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

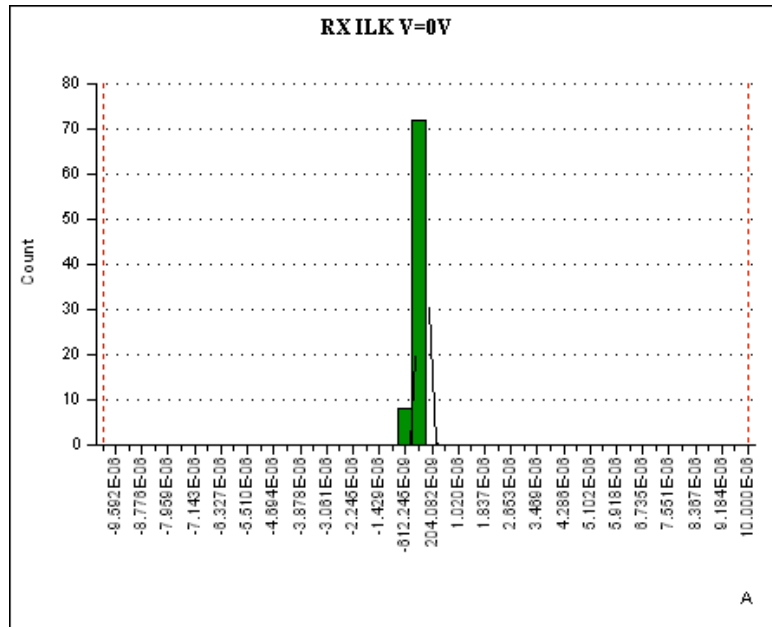
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=7.000, Test.Name=RX ILK V=0V



Statistics: (A)

Max	-77.513E-09	25%	-174.220E-09	SpecHigh	10.000E-06
Mean	-185.684E-09	10%	-413.351E-09	SpecLow	-10.000E-06
Min	-583.481E-09	N	80	PctWithinSpec	100.00
Range	505.969E-09	Cp	>4.0000	PctDefSpec	0
StdDev	114.149E-09	Cpl	>4.0000	NWithinSpec	80
W	0.6336	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	-116.636E-09	Skew	-2.1591		
75%	-130.194E-09	Kurtosis	3.6188		
Median	-141.872E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

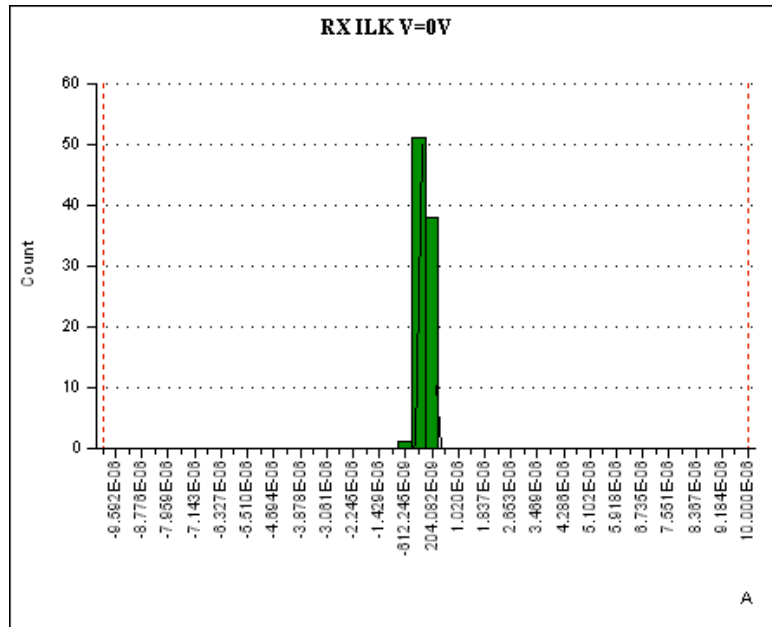
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.001, Test.Name=RX ILK V=0V



Statistics: (A)

Max	38.794E-09	25%	-31.927E-09	SpecHigh	10.000E-06
Mean	-46.821E-09	10%	-231.019E-09	SpecLow	-10.000E-06
Min	-542.546E-09	N	90	PctWithinSpec	100.00
Range	581.340E-09	Cp	>4.0000	PctDefSpec	0
StdDev	108.773E-09	Cpl	>4.0000	NWithinSpec	90
W	0.6485	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	18.509E-09	Skew	-2.2441		
75%	13.540E-09	Kurtosis	5.0720		
Median	-4.384E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

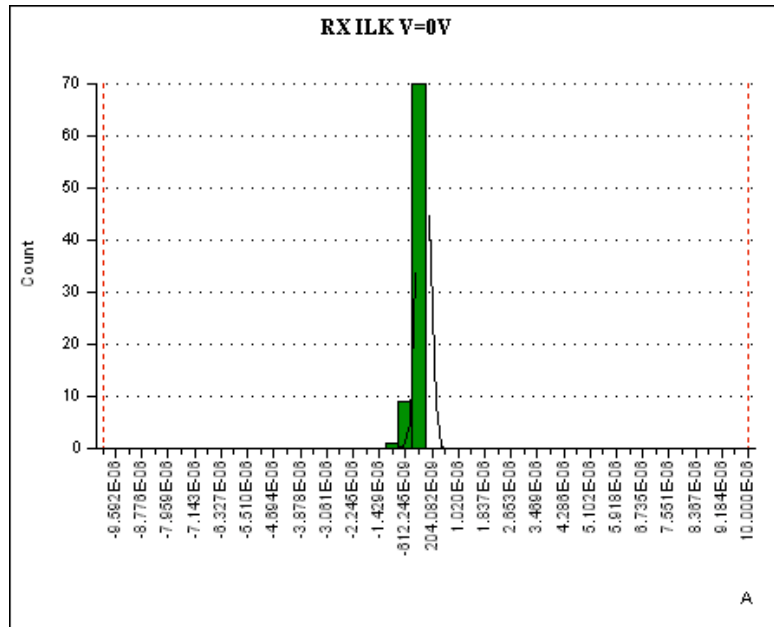
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=7.001, Test.Name=RX ILK V=0V



Statistics: (A)

Max	-51.725E-09	25%	-258.804E-09	SpecHigh	10.000E-06
Mean	-176.443E-09	10%	-437.334E-09	SpecLow	-10.000E-06
Min	-867.012E-09	N	80	PctWithinSpec	100.00
Range	815.288E-09	Cp	>4.0000	PctDefSpec	0
StdDev	182.237E-09	Cpl	>4.0000	NWithinSpec	80
W	0.6817	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	-62.739E-09	Skew	-1.9596		
75%	-68.155E-09	Kurtosis	3.6445		
Median	-81.381E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

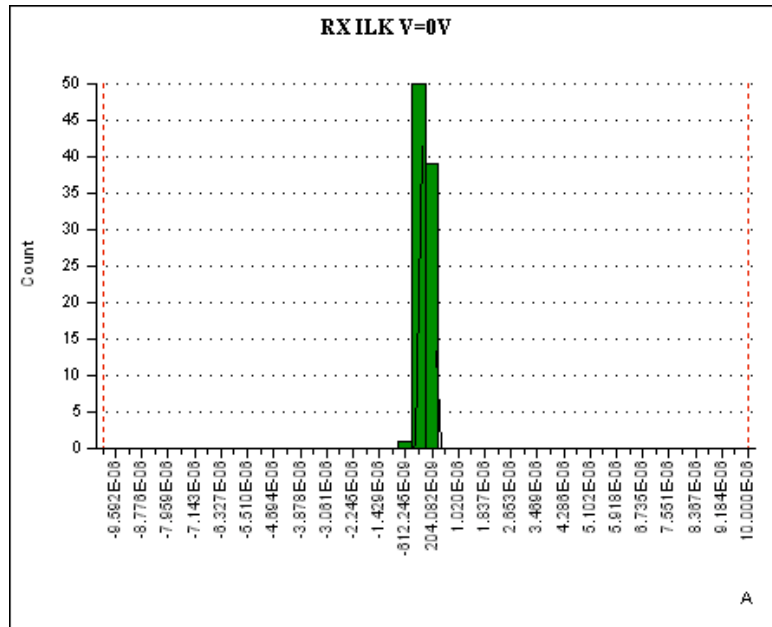
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.002, Test.Name=RX ILK V=0V



Statistics: (A)

Max	296.995E-09	25%	-23.892E-09	SpecHigh	10.000E-06
Mean	-33.235E-09	10%	-143.190E-09	SpecLow	-10.000E-06
Min	-646.456E-09	N	90	PctWithinSpec	100.00
Range	943.451E-09	Cp	>4.0000	PctDefSpec	0
StdDev	108.561E-09	Cpl	>4.0000	NWithinSpec	90
W	0.6325	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	19.392E-09	Skew	-2.7678		
75%	15.235E-09	Kurtosis	13.2961		
Median	-3.721E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

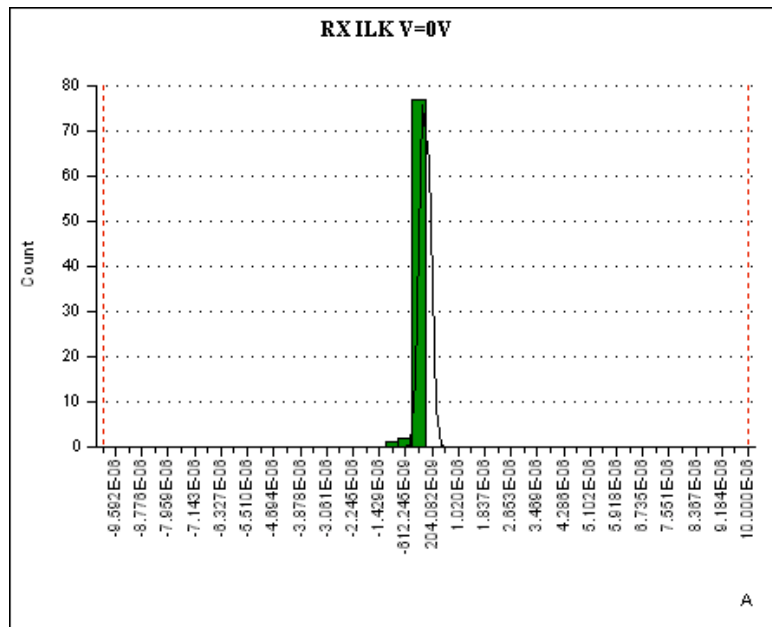
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=7.002, Test.Name=RX ILK V=0V



Statistics: (A)

Max	-22.107E-09	25%	-172.526E-09	SpecHigh	10.000E-06
Mean	-120.301E-09	10%	-352.268E-09	SpecLow	-10.000E-06
Min	-887.202E-09	N	80	PctWithinSpec	100.00
Range	865.095E-09	Cp	>4.0000	c	
StdDev	148.803E-09	Cpl	>4.0000	PctDefSpec	0
W	0.6543	Cpu	>4.0000	NWithinSpec	80
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	-29.582E-09	Skew	-2.4384		
75%	-34.665E-09	Kurtosis	8.0348		
Median	-42.919E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

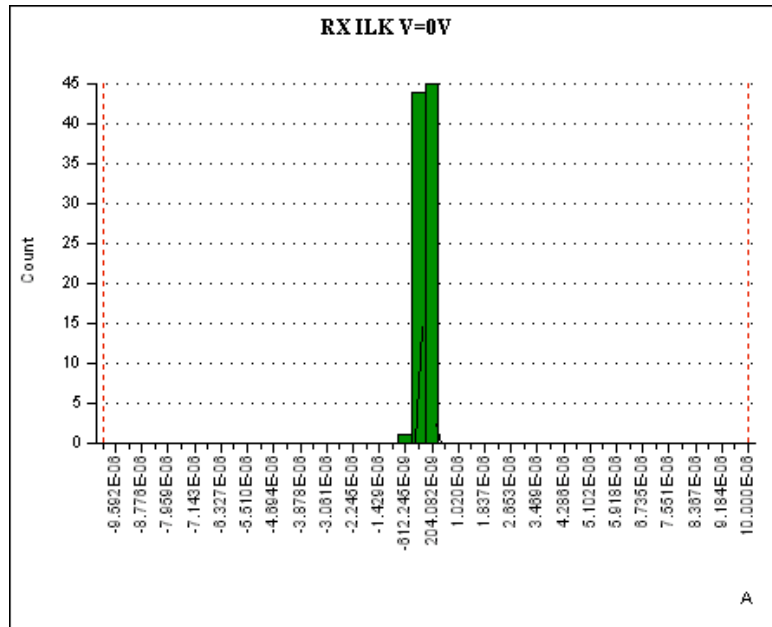
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.003, Test.Name=RX ILK V=0V



Statistics: (A)

Max	23.557E-09	25%	-25.735E-09	SpecHigh	10.000E-06
Mean	-26.587E-09	10%	-132.871E-09	SpecLow	-10.000E-06
Min	-410.946E-09	N	90	PctWithinSpec	100.00
Range	434.503E-09	Cp	>4.0000	PctDefSpec	0
StdDev	76.492E-09	Cpl	>4.0000	NWithinSpec	90
W	0.6361	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	21.163E-09	Skew	-2.7719		
75%	17.516E-09	Kurtosis	8.7666		
Median	-38.528E-12				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

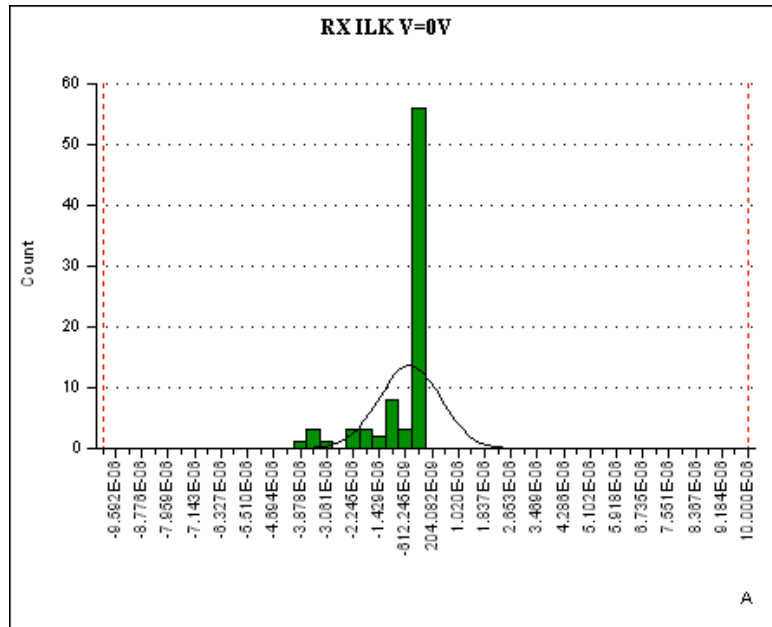
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=7.003, Test.Name=RX ILK V=0V



Statistics: (A)

Max	-50.469E-09	25%	-888.157E-09	SpecHigh	10.000E-06
Mean	-593.963E-09	10%	-2.106E-06	SpecLow	-10.000E-06
Min	-3.959E-06	N	80	PctWithinSpec	100.00
Range	3.909E-06	Cp	3.5092	c	
StdDev	949.883E-09	Cpl	3.3008	PctDefSpec	0
W	0.6283	Cpu	3.7176	NWithinSpec	80
WpValue	0.0000	Cpk	3.3008	NOutsideSpec	0
90%	-64.212E-09	Skew	-2.0021		
75%	-71.507E-09	Kurtosis	3.2508		
Median	-81.897E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

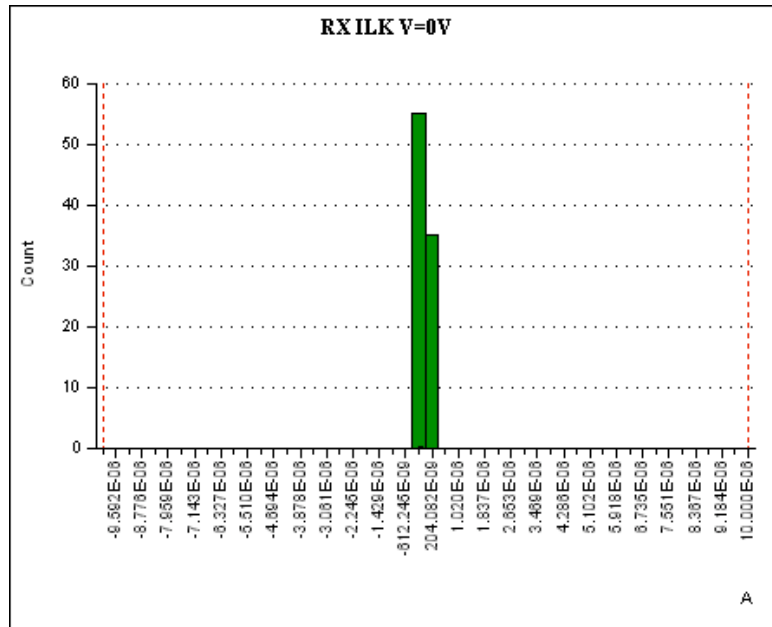
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.004, Test.Name=RX ILK V=0V



Statistics: (A)

Max	47.060E-09	25%	-26.619E-09	SpecHigh	10.000E-06
Mean	-17.883E-09	10%	-61.551E-09	SpecLow	-10.000E-06
Min	-264.611E-09	N	90	PctWithinSpec	100.00
Range	311.671E-09	Cp	>4.0000	PctDefSpec	0
StdDev	47.242E-09	Cpl	>4.0000	NWithinSpec	90
W	0.7341	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	17.740E-09	Skew	-2.7209		
75%	14.793E-09	Kurtosis	9.9974		
Median	-9.433E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

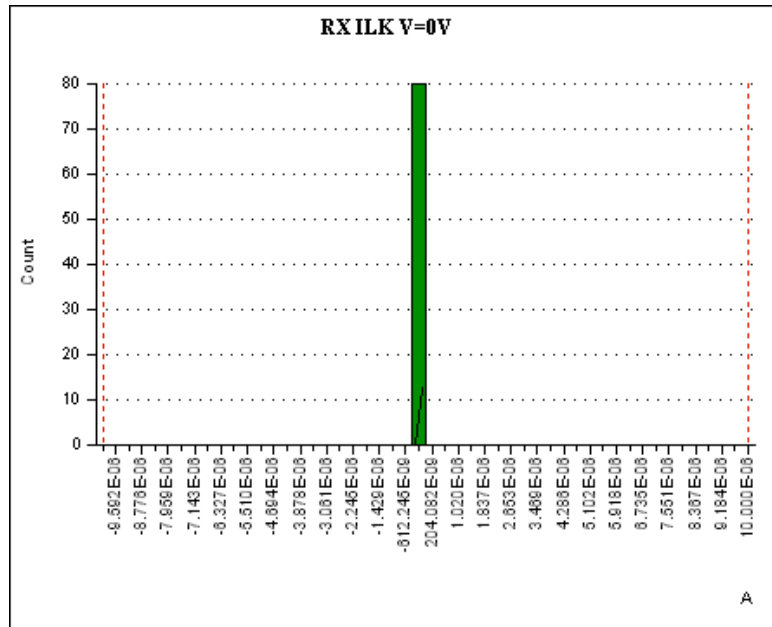
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=7.004, Test.Name=RX ILK V=0V



Statistics: (A)

Max	-14.147E-09	25%	-85.140E-09	SpecHigh	10.000E-06
Mean	-67.827E-09	10%	-150.860E-09	SpecLow	-10.000E-06
Min	-332.153E-09	N	80	PctWithinSpec	100.00
Range	318.006E-09	Cp	>4.0000	c	
StdDev	54.565E-09	Cpl	>4.0000	PctDefSpec	0
W	0.7742	Cpu	>4.0000	NWithinSpec	80
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	-23.911E-09	Skew	-2.1205		
75%	-33.855E-09	Kurtosis	6.1287		
Median	-44.722E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

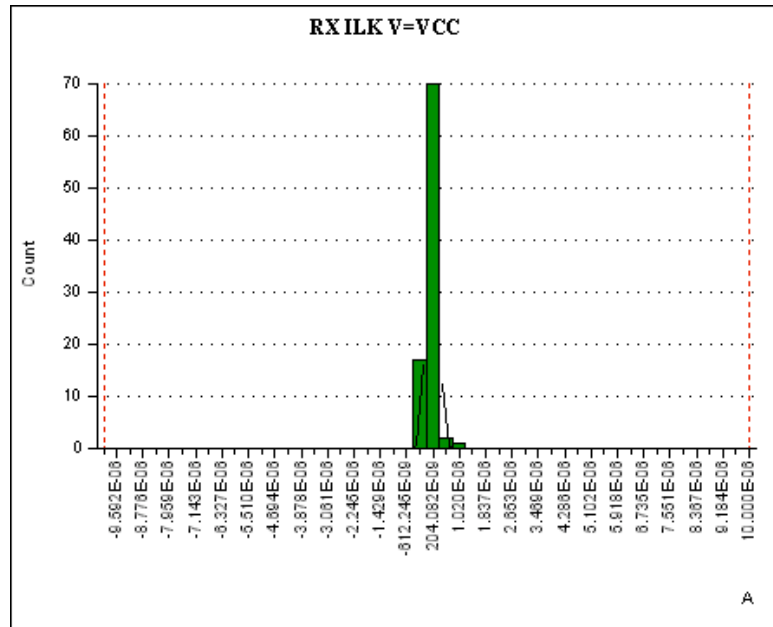
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.005, Test.Name=RX ILK V=VCC



Statistics: (A)

Max	943.726E-09	25%	6.263E-09	SpecHigh	10.000E-06
Mean	89.091E-09	10%	-6.486E-09	SpecLow	-10.000E-06
Min	-18.419E-09	N	90	PctWithinSpec	100.00
Range	962.145E-09	Cp	>4.0000	PctDefSpec	0
StdDev	153.265E-09	Cpl	>4.0000	NWithinSpec	90
W	0.6480	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	311.258E-09	Skew	2.7311		
75%	133.345E-09	Kurtosis	10.3196		
Median	17.739E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

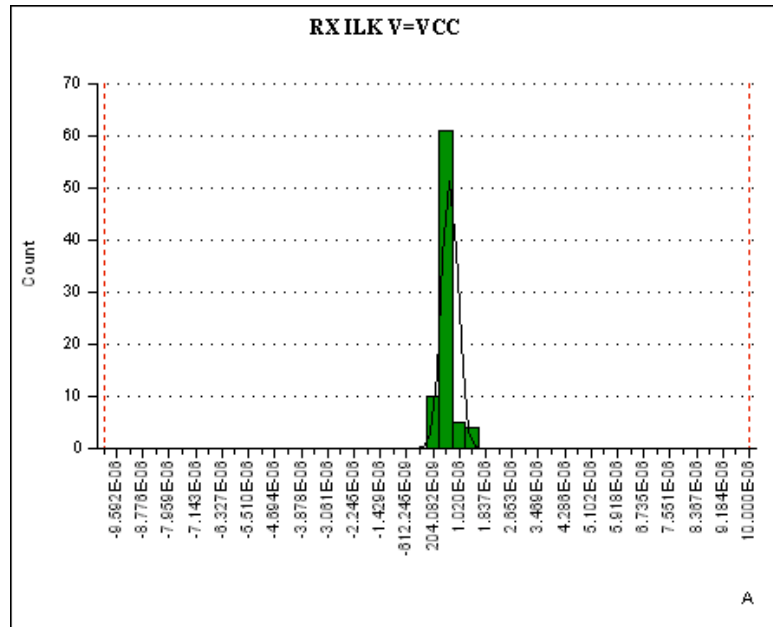
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=7.005, Test.Name=RX ILK V=VCC



Statistics: (A)

Max	1.624E-06	25%	492.456E-09	SpecHigh	10.000E-06
Mean	604.929E-09	10%	389.927E-09	SpecLow	-10.000E-06
Min	285.296E-09	N	80	PctWithinSpec	100.00
Range	1.339E-06	Cp	>4.0000	c	
StdDev	254.249E-09	Cpl	>4.0000	PctDefSpec	0
W	0.7352	Cpu	>4.0000	NWithinSpec	80
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	939.558E-09	Skew	2.1901		
75%	625.157E-09	Kurtosis	5.0188		
Median	528.374E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

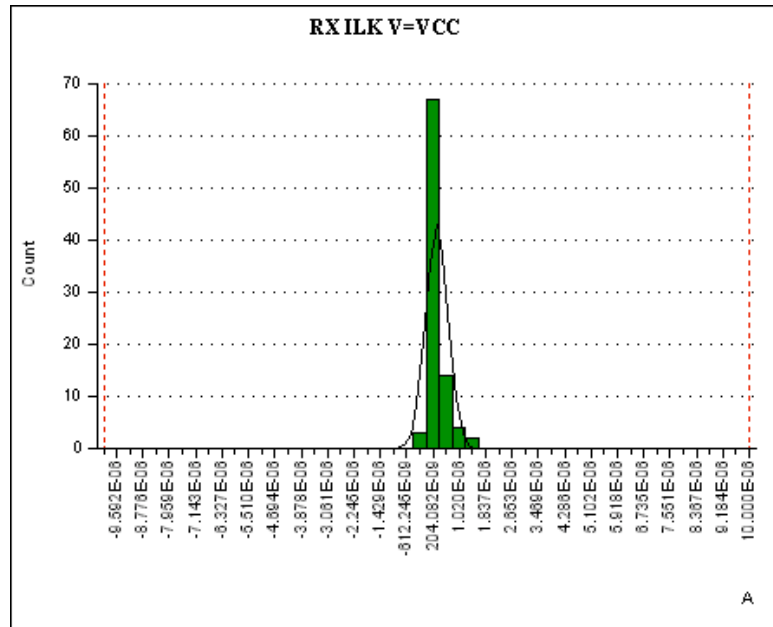
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.006, Test.Name=RX ILK V=VCC



Statistics: (A)

Max	1.342E-06	25%	13.114E-09	SpecHigh	10.000E-06
Mean	210.472E-09	10%	5.230E-09	SpecLow	-10.000E-06
Min	-5.529E-09	N	90	PctWithinSpec	100.00
Range	1.348E-06	Cp	>4.0000	PctDefSpec	0
StdDev	339.773E-09	Cpl	>4.0000	NWithinSpec	90
W	0.6568	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	740.204E-09	Skew	1.6160		
75%	364.864E-09	Kurtosis	1.5438		
Median	22.525E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

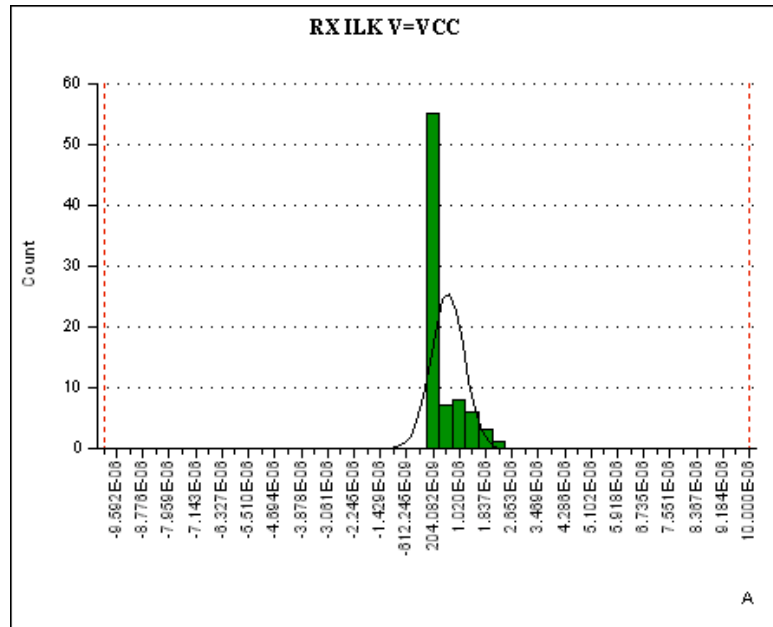
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=7.006, Test.Name=RX ILK V=VCC



Statistics: (A)

Max	2.372E-06	25%	251.552E-09	SpecHigh	10.000E-06
Mean	546.461E-09	10%	249.674E-09	SpecLow	-10.000E-06
Min	228.711E-09	N	80	PctWithinSpec	100.00
Range	2.143E-06	Cp	>4.0000	PctDefSpec	0
StdDev	507.678E-09	Cpl	>4.0000	NWithinSpec	80
W	0.6554	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	1.389E-06	Skew	1.7995		
75%	716.044E-09	Kurtosis	2.4522		
Median	265.221E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

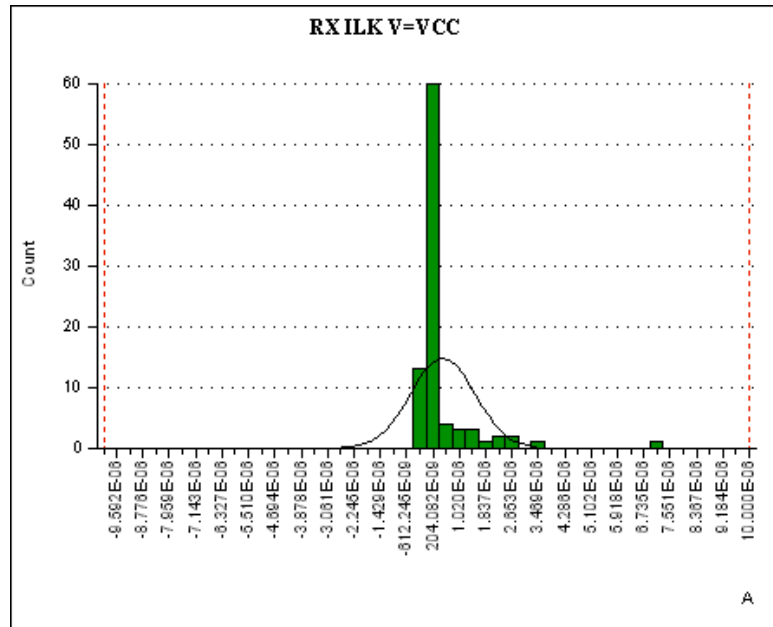
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.007, Test.Name=RX ILK V=VCC



Statistics: (A)

Max	7.066E-06	25%	10.830E-09	SpecHigh	10.000E-06
Mean	384.992E-09	10%	-5.455E-09	SpecLow	-10.000E-06
Min	-15.918E-09	N	90	PctWithinSpec	100.00
Range	7.082E-06	Cp	3.3855	PctDefSpec	0
StdDev	984.587E-09	Cpl	3.5159	NWithinSpec	90
W	0.4424	Cpu	3.2552	NOutsideSpec	0
WpValue	0.0000	Cpk	3.2552		
90%	1.410E-06	Skew	4.4007		
75%	176.752E-09	Kurtosis	24.5838		
Median	23.667E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

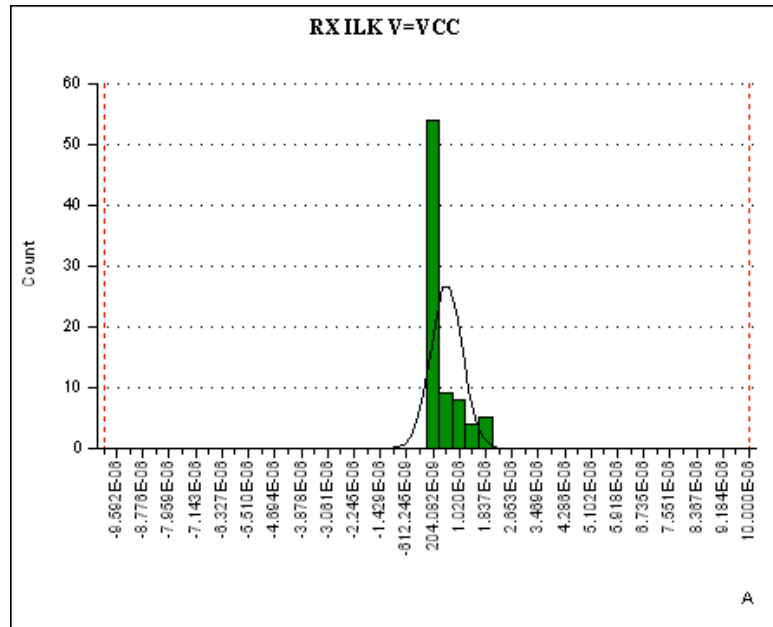
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=7.007, Test.Name=RX ILK V=VCC



Statistics: (A)

Max	2.028E-06	25%	217.030E-09	SpecHigh	10.000E-06
Mean	507.057E-09	10%	210.437E-09	SpecLow	-10.000E-06
Min	192.236E-09	N	80	PctWithinSpec	100.00
Range	1.836E-06	Cp	>4.0000	PctDefSpec	0
StdDev	480.390E-09	Cpl	>4.0000	NWithinSpec	80
W	0.6770	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	1.265E-06	Skew	1.6217		
75%	627.182E-09	Kurtosis	1.5578		
Median	228.083E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

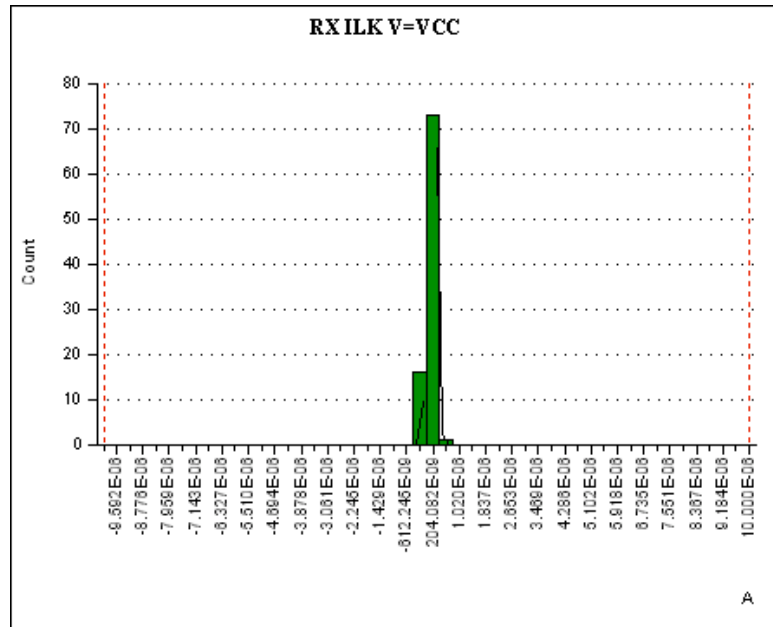
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.008, Test.Name=RX ILK V=VCC



Statistics: (A)

Max	811.614E-09	25%	13.925E-09	SpecHigh	10.000E-06
Mean	67.012E-09	10%	-3.463E-09	SpecLow	-10.000E-06
Min	-12.749E-09	N	90	PctWithinSpec	100.00
Range	824.363E-09	Cp	>4.0000	PctDefSpec	0
StdDev	118.495E-09	Cpl	>4.0000	NWithinSpec	90
W	0.5784	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	194.756E-09	Skew	3.6509		
75%	69.245E-09	Kurtosis	17.7034		
Median	26.764E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

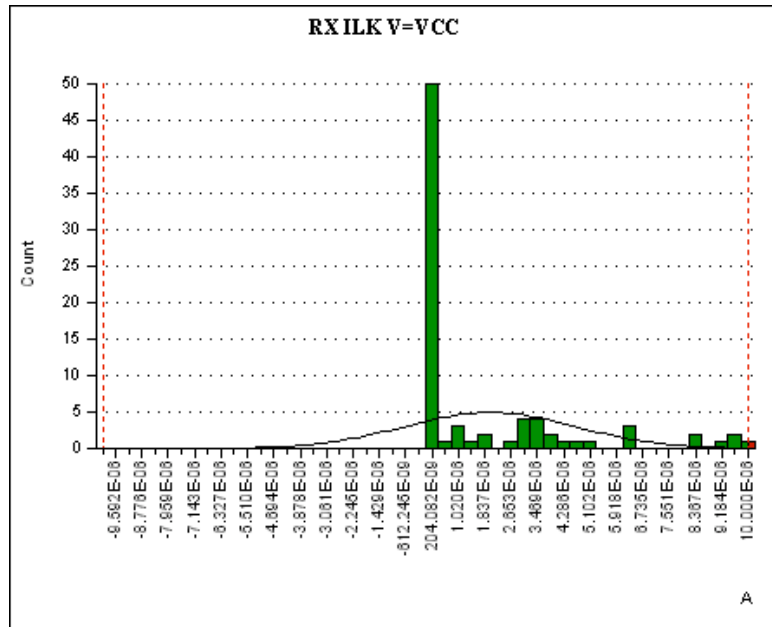
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=7.008, Test.Name=RX ILK V=VCC



Statistics: (A)

Max	9.855E-06	25%	355.960E-09	SpecHigh	10.000E-06
Mean	1.894E-06	10%	344.244E-09	SpecLow	-10.000E-06
Min	334.000E-09	N	80	PctWithinSpec	100.00
Range	9.521E-06	Cp	1.2631	c	
StdDev	2.639E-06	Cpl	1.5023	PctDefSpec	0
W	0.6478	Cpu	1.0239	NWithinSpec	80
WpValue	0.0000	Cpk	1.0239	NOutsideSpec	0
90%	6.204E-06	Skew	1.8015		
75%	3.216E-06	Kurtosis	2.3047		
Median	373.976E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

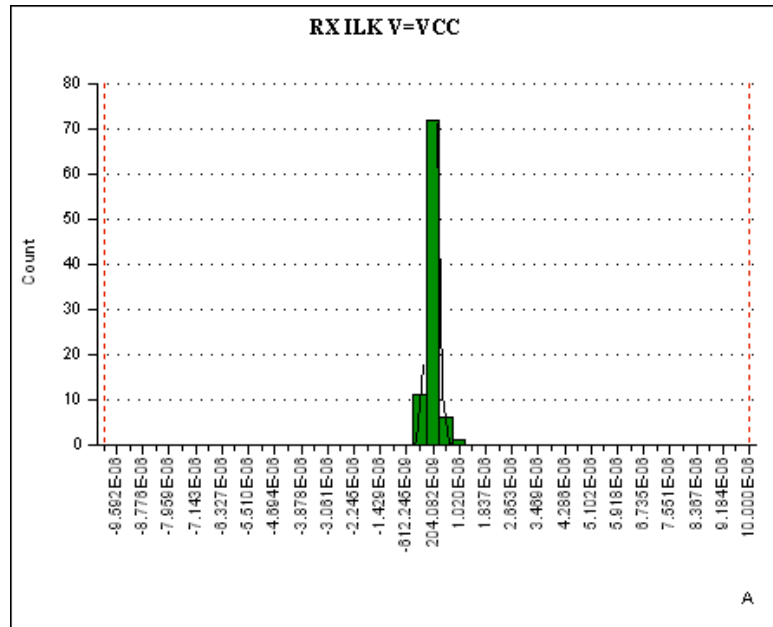
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.009, Test.Name=RX ILK V=VCC



Statistics: (A)

Max	949.900E-09	25%	14.129E-09	SpecHigh	10.000E-06
Mean	81.921E-09	10%	-2.950E-09	SpecLow	-10.000E-06
Min	-11.128E-09	N	90	PctWithinSpec	100.00
Range	961.028E-09	Cp	>4.0000	PctDefSpec	0
StdDev	153.635E-09	Cpl	>4.0000	NWithinSpec	90
W	0.5573	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	270.216E-09	Skew	3.2486		
75%	80.884E-09	Kurtosis	12.5296		
Median	24.663E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

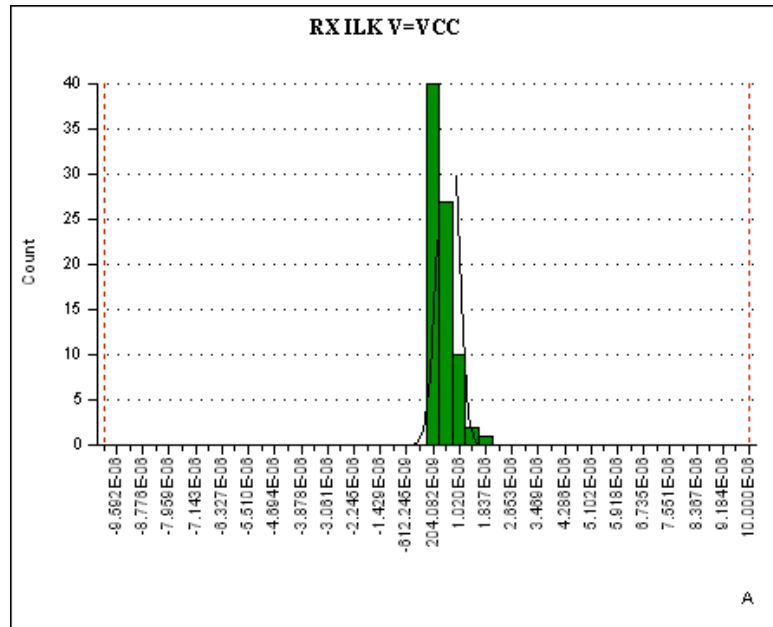
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=7.009, Test.Name=RX ILK V=VCC



Statistics: (A)

Max	1.682E-06	25%	388.601E-09	SpecHigh	10.000E-06
Mean	537.277E-09	10%	379.574E-09	SpecLow	-10.000E-06
Min	330.097E-09	N	80	PctWithinSpec	100.00
Range	1.352E-06	Cp	>4.0000	c	
StdDev	285.013E-09	Cpl	>4.0000	PctDefSpec	0
W	0.6226	Cpu	>4.0000	NWithinSpec	80
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	1.012E-06	Skew	2.1640		
75%	527.418E-09	Kurtosis	4.1921		
Median	407.574E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

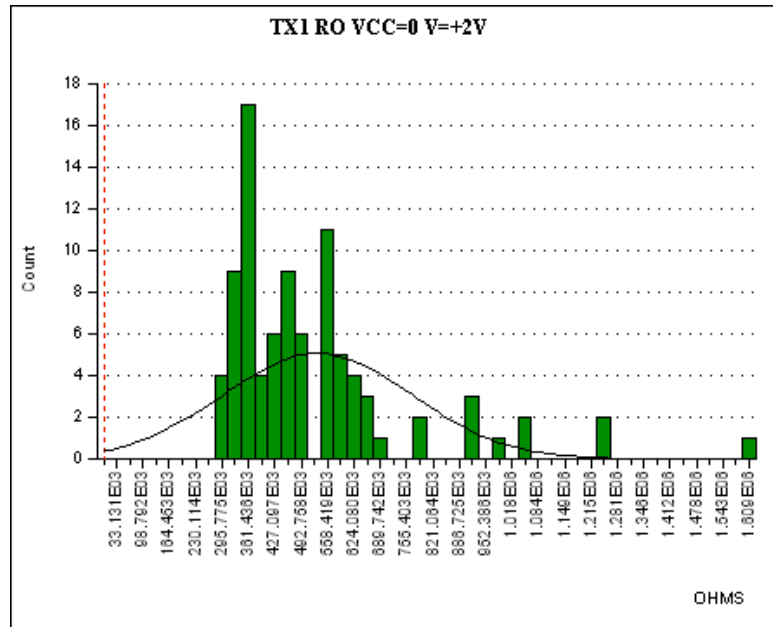
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=8.000, Test.Name=TX1 RO VCC=0 V=+2V



Statistics: (OHMS)

Max	1.609E06	25%	363.550E03	SpecHigh	N/A
Mean	528.219E03	10%	331.417E03	SpecLow	300.000
Min	294.444E03	N	90	PctWithinSpec	100.00
Range	1.315E06	Cp	N/A	c	
StdDev	232.946E03	Cpl	0.7554	PctDefSpec	0
W	0.7791	Cpu	N/A	NWithinSpec	90
WpValue	0.0000	Cpk	0.7554	NOutsideSpec	0
90%	857.563E03	Skew	2.1471		
75%	592.370E03	Kurtosis	5.7225		
Median	467.059E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

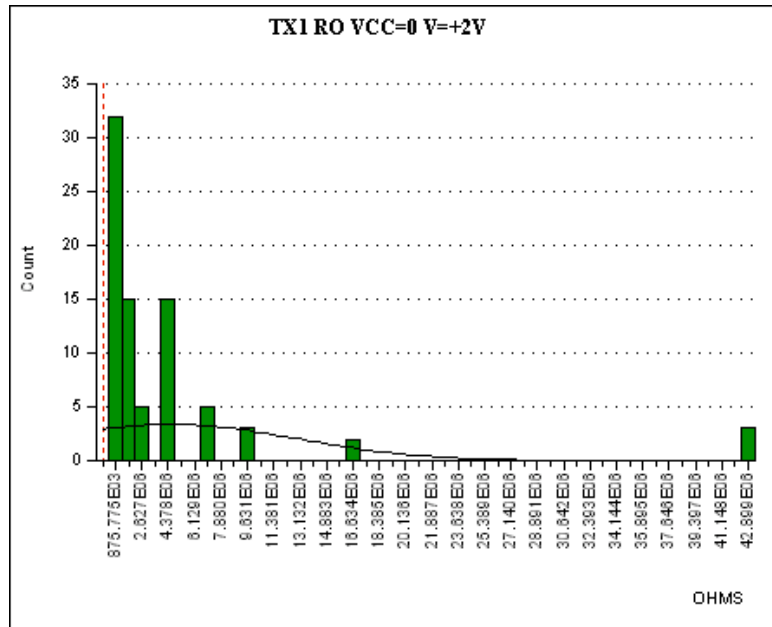
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=8.000, Test.Name=TX1 RO VCC=0 V=+2V



Statistics: (OHMS)

Max	42.899E06	25%	945.027E03	SpecHigh	N/A
Mean	4.476E06	10%	783.972E03	SpecLow	300.000
Min	489.933E03	N	80	PctWithinSpec	100.00
Range	42.409E06	Cp	N/A	PctDefSpec	0
StdDev	8.248E06	Cpl	0.1809	NWithinSpec	80
W	0.4505	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	0.1809		
90%	8.656E06	Skew	3.9679		
75%	4.110E06	Kurtosis	16.2061		
Median	1.688E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

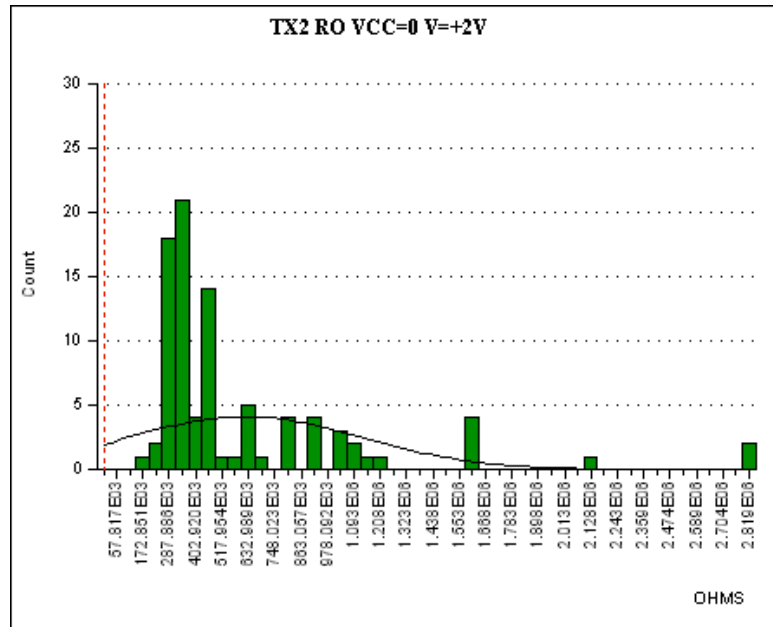
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=8.003, Test.Name=TX2 RO VCC=0 V=+2V



Statistics: (OHMS)

Max	2.819E06	25%	331.417E03	SpecHigh	N/A
Mean	612.679E03	10%	292.789E03	SpecLow	300.000
Min	188.637E03	N	90	PctWithinSpec	100.00
Range	2.630E06	Cp	N/A	PctDefSpec	0
StdDev	501.391E03	Cpl	0.4071	NWithinSpec	90
W	0.6723	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	0.4071		
90%	1.103E06	Skew	2.6126		
75%	703.498E03	Kurtosis	7.8191		
Median	408.855E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

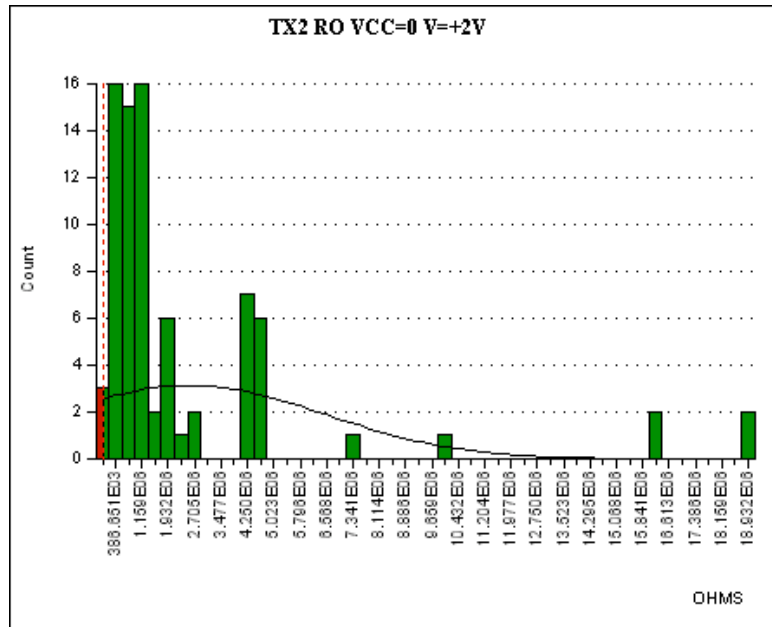
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=8.003, Test.Name=TX2 RO VCC=0 V=+2V



Statistics: (OHMS)

Max	18.932E06	25%	616.497E03	SpecHigh	N/A
Mean	2.535E06	10%	321.769E03	SpecLow	300.000
Min	120.663E03	N	80	PctWithinSpec	100.00
Range	18.811E06	Cp	N/A	c	
StdDev	3.918E06	Cpl	0.2157	PctDefSpec	0
W	0.5618	Cpu	N/A	NWithinSpec	80
WpValue	0.0000	Cpk	0.2157	NOutsideSpec	0
90%	4.677E06	Skew	3.0824		
75%	2.527E06	Kurtosis	9.6392		
Median	1.026E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

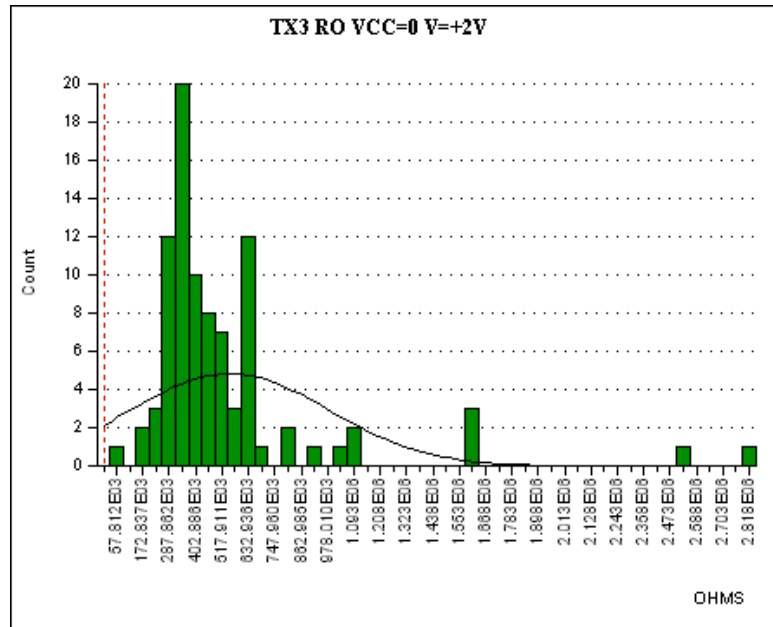
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=8.004, Test.Name=TX3 RO VCC=0 V=+2V



Statistics: (OHMS)

Max	2.818E06	25%	349.046E03	SpecHigh	N/A
Mean	546.671E03	10%	301.008E03	SpecLow	300.000
Min	64.484E03	N	90	PctWithinSpec	100.00
Range	2.754E06	Cp	N/A	PctDefSpec	0
StdDev	427.474E03	Cpl	0.4260	NWithinSpec	90
W	0.6158	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	0.4260		
90%	857.554E03	Skew	3.4070		
75%	620.381E03	Kurtosis	13.7639		
Median	408.855E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

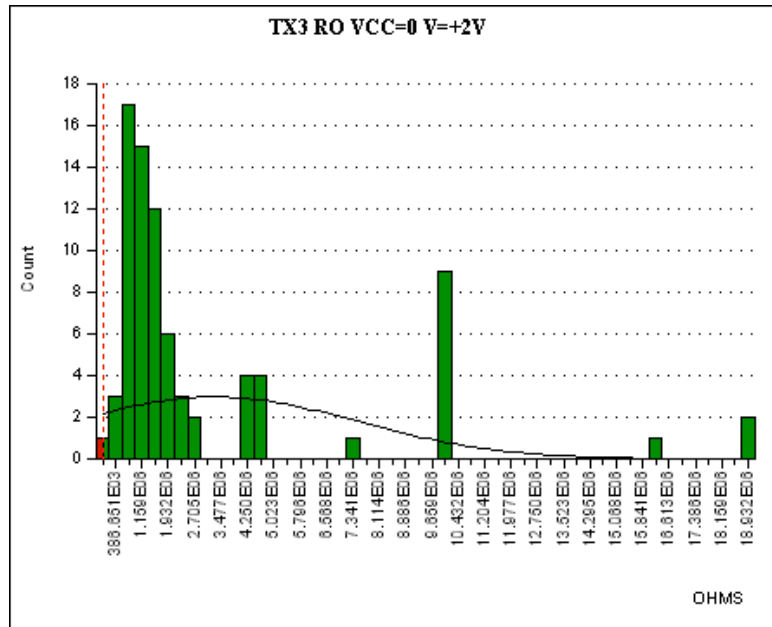
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=8.004, Test.Name=TX3 RO VCC=0 V=+2V



Statistics: (OHMS)

Max	18.932E06	25%	863.848E03	SpecHigh	N/A
Mean	3.260E06	10%	781.718E03	SpecLow	300.000
Min	162.490E03	N	80	PctWithinSpec	100.00
Range	18.769E06	Cp	N/A	PctDefSpec	0
StdDev	4.146E06	Cpl	0.2621	NWithinSpec	80
W	0.6496	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	0.2621		
90%	10.050E06	Skew	2.2223		
75%	4.109E06	Kurtosis	4.7285		
Median	1.413E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

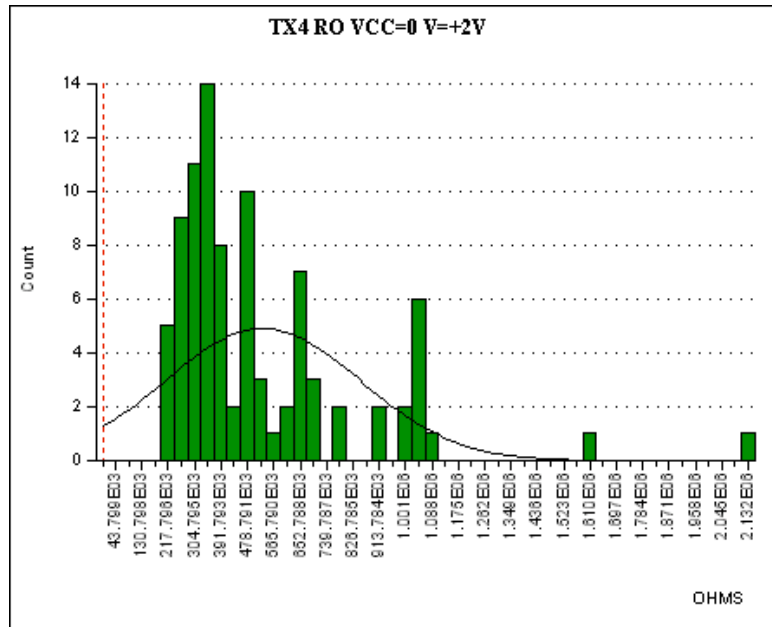
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=8.007, Test.Name=TX4 RO VCC=0 V=+2V



Statistics: (OHMS)

Max	2.132E06	25%	311.736E03	SpecHigh	N/A
Mean	523.320E03	10%	262.102E03	SpecLow	300.000
Min	216.666E03	N	90	PctWithinSpec	100.00
Range	1.915E06	Cp	N/A	PctDefSpec	0
StdDev	316.730E03	Cpl	0.5504	NWithinSpec	90
W	0.7724	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	0.5504		
90%	1.017E06	Skew	2.2933		
75%	635.397E03	Kurtosis	7.5084		
Median	408.850E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

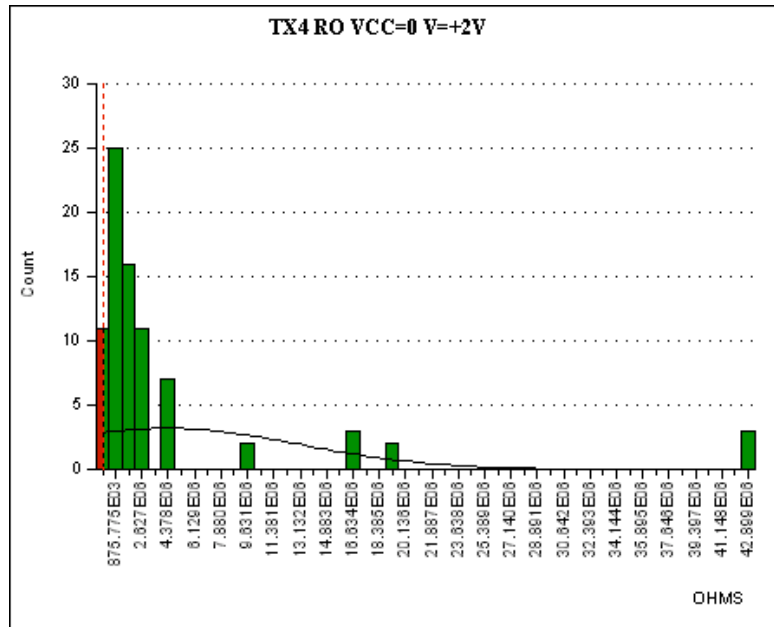
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=8.007, Test.Name=TX4 RO VCC=0 V=+2V



Statistics: (OHMS)

Max	42.899E06	25%	590.025E03	SpecHigh	N/A
Mean	4.240E06	10%	385.763E03	SpecLow	300.000
Min	101.136E03	N	80	PctWithinSpec	100.00
Range	42.797E06	Cp	N/A	PctDefSpec	0
StdDev	8.742E06	Cpl	0.1617	NWithinSpec	80
W	0.4597	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	0.1617		
90%	13.159E06	Skew	3.5502		
75%	2.504E06	Kurtosis	12.8826		
Median	1.410E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

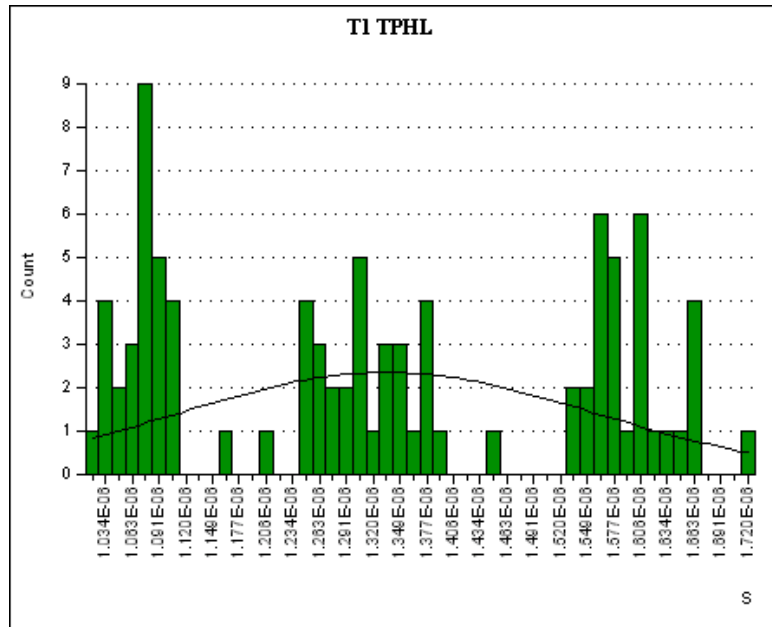
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=9.000, Test.Name=T1 TPHL



Statistics: (S)

Max	1.720E-06	25%	1.090E-06	SpecHigh	N/A
Mean	1.332E-06	10%	1.060E-06	SpecLow	N/A
Min	1.020E-06	N	90	PctWithinSpec	N/A
Range	700.000E-09	Cp	N/A	PctDefSpec	N/A
StdDev	218.168E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8995	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.610E-06	Skew	0.1184		
75%	1.570E-06	Kurtosis	-1.4277		
Median	1.310E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

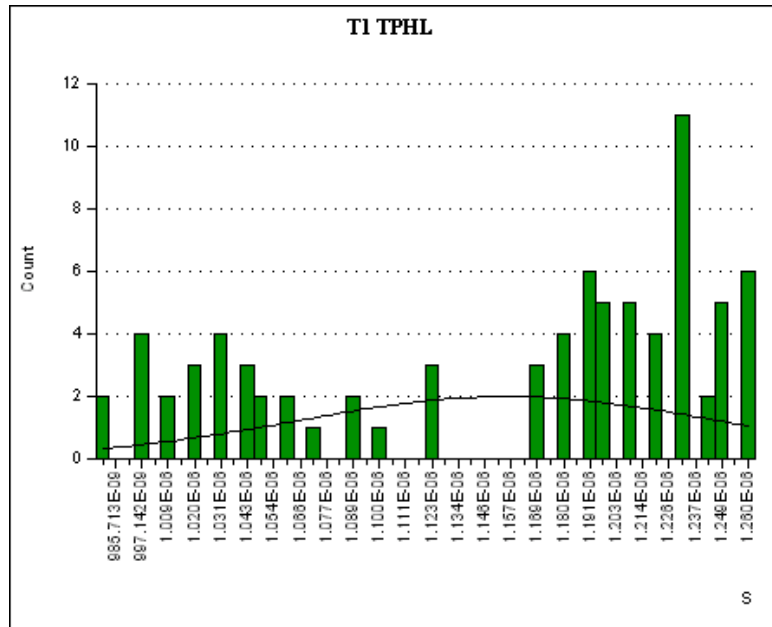
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=9.000, Test.Name=T1 TPHL



Statistics: (S)

Max	1.260E-06	25%	1.055E-06	SpecHigh	N/A
Mean	1.154E-06	10%	1.015E-06	SpecLow	N/A
Min	979.999E-09	N	80	PctWithinSpec	N/A
Range	280.000E-09	Cp	N/A	c	
StdDev	91.329E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8569	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	1.250E-06	Skew	-0.6035		
75%	1.230E-06	Kurtosis	-1.2163		
Median	1.190E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

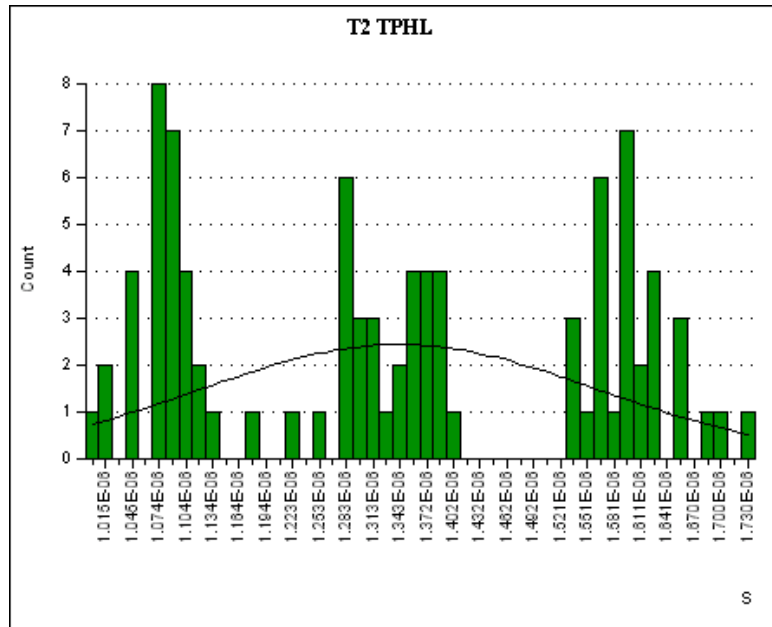
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.001, Test.Name=T2 TPHL



Statistics: (S)

Max	1.730E-06	25%	1.100E-06	SpecHigh	N/A
Mean	1.338E-06	10%	1.070E-06	SpecLow	N/A
Min	999.999E-09	N	90	PctWithinSpec	N/A
Range	730.000E-09	Cp	N/A	PctDefSpec	N/A
StdDev	219.046E-09	Cpl	N/A	NWithinSpec	N/A
W	0.9111	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.620E-06	Skew	0.0749		
75%	1.560E-06	Kurtosis	-1.3875		
Median	1.340E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

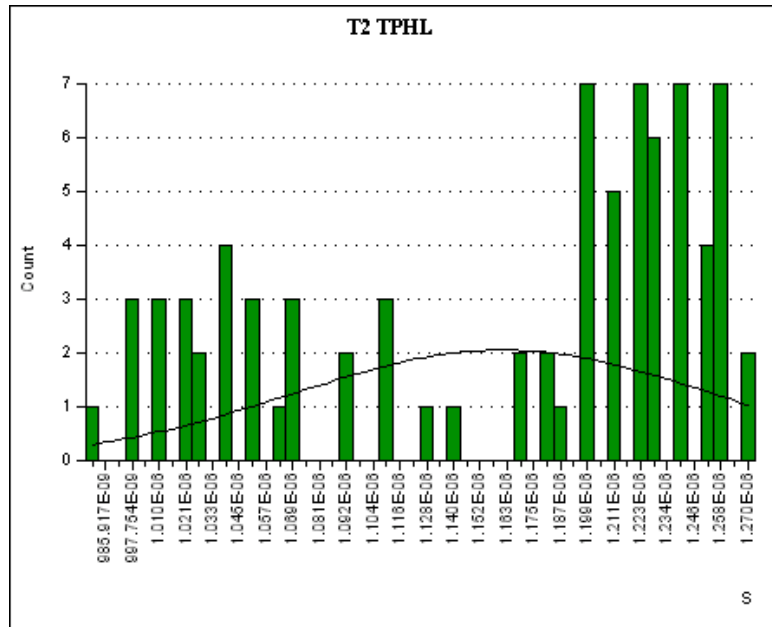
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=9.001, Test.Name=T2 TPHL



Statistics: (S)

Max	1.270E-06	25%	1.065E-06	SpecHigh	N/A
Mean	1.160E-06	10%	1.020E-06	SpecLow	N/A
Min	979.999E-09	N	80	PctWithinSpec	N/A
Range	290.000E-09	Cp	N/A	PctDefSpec	N/A
StdDev	91.934E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8556	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.260E-06	Skew	-0.5841		
75%	1.235E-06	Kurtosis	-1.2627		
Median	1.200E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

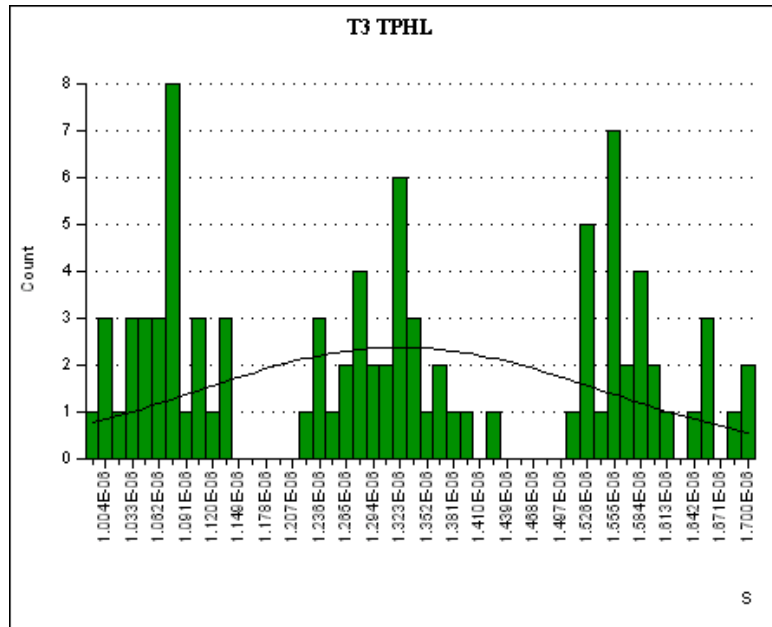
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.002, Test.Name=T3 TPHL



Statistics: (S)

Max	1.700E-06	25%	1.090E-06	SpecHigh	N/A
Mean	1.320E-06	10%	1.050E-06	SpecLow	N/A
Min	989.999E-09	N	90	PctWithinSpec	N/A
Range	710.000E-09	Cp	N/A	c	
StdDev	218.413E-09	Cpl	N/A	PctDefSpec	N/A
W	0.9212	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	1.600E-06	Skew	0.1136		
75%	1.550E-06	Kurtosis	-1.3444		
Median	1.315E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

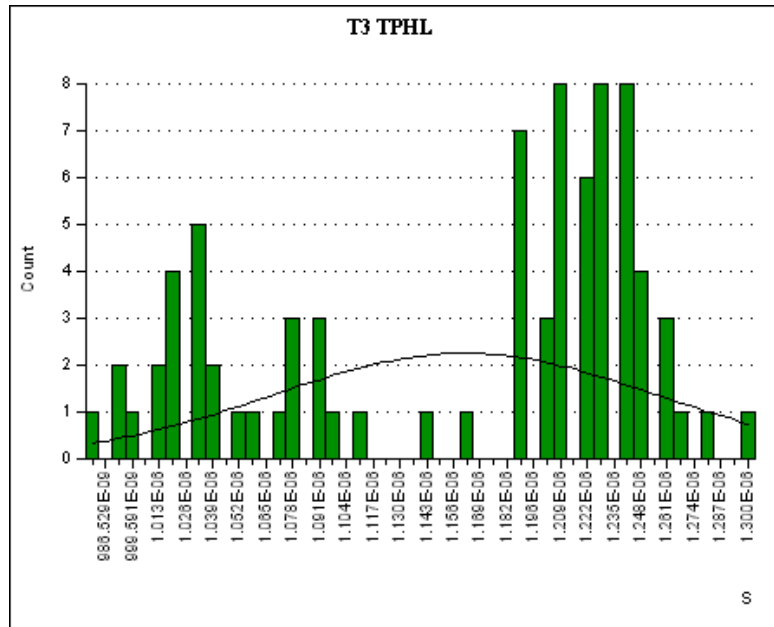
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=9.002, Test.Name=T3 TPHL



Statistics: (S)

Max	1.300E-06	25%	1.075E-06	SpecHigh	N/A
Mean	1.160E-06	10%	1.020E-06	SpecLow	N/A
Min	979.999E-09	N	80	PctWithinSpec	N/A
Range	320.000E-09	Cp	N/A	c	
StdDev	92.415E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8596	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	1.250E-06	Skew	-0.6072		
75%	1.230E-06	Kurtosis	-1.1938		
Median	1.205E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

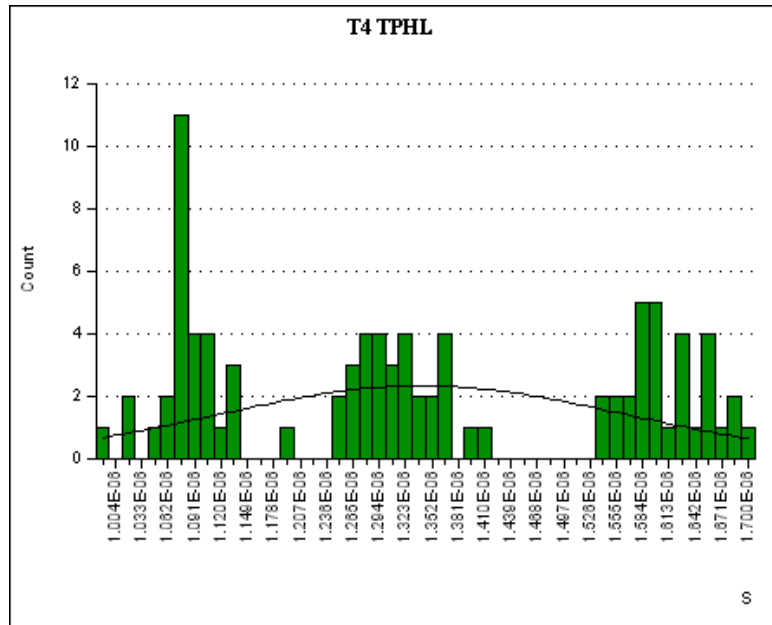
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.003, Test.Name=T4 TPHL



Statistics: (S)

Max	1.700E-06	25%	1.100E-06	SpecHigh	N/A
Mean	1.338E-06	10%	1.070E-06	SpecLow	N/A
Min	989.999E-09	N	90	PctWithinSpec	N/A
Range	710.000E-09	Cp	N/A	PctDefSpec	N/A
StdDev	221.791E-09	Cpl	N/A	NWithinSpec	N/A
W	0.9000	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.635E-06	Skew	0.1533		
75%	1.580E-06	Kurtosis	-1.4127		
Median	1.310E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

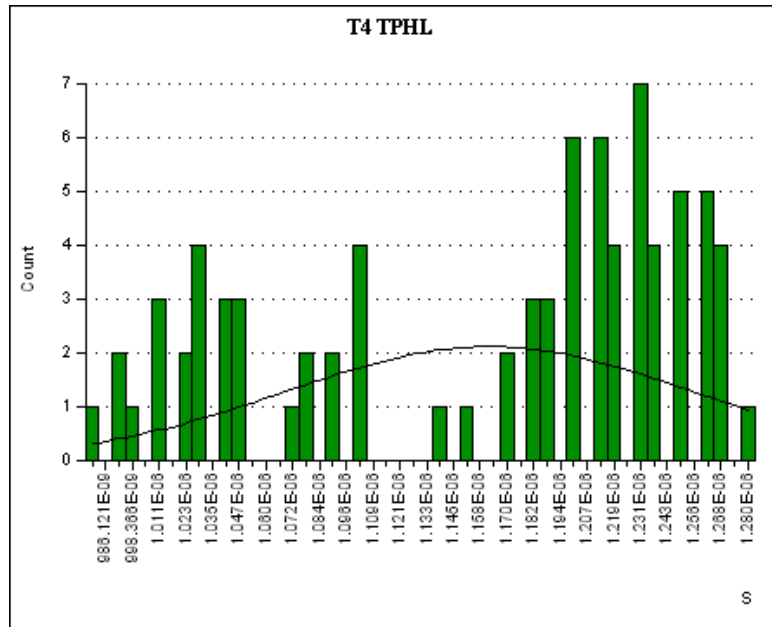
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=9.003, Test.Name=T4 TPHL



Statistics: (S)

Max	1.280E-06	25%	1.075E-06	SpecHigh	N/A
Mean	1.160E-06	10%	1.020E-06	SpecLow	N/A
Min	979.999E-09	N	80	PctWithinSpec	N/A
Range	300.000E-09	Cp	N/A	PctDefSpec	N/A
StdDev	92.195E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8771	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.260E-06	Skew	-0.5656		
75%	1.230E-06	Kurtosis	-1.1974		
Median	1.200E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

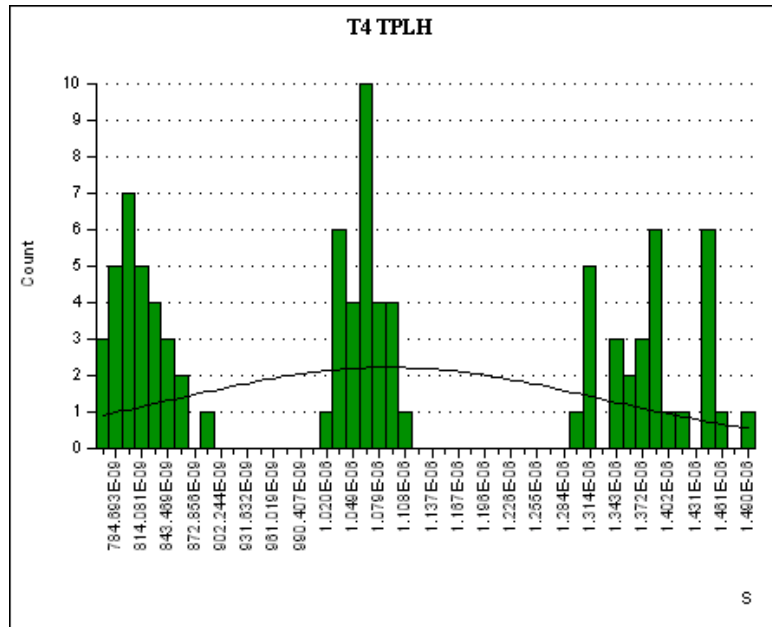
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.004, Test.Name=T4 TPLH



Statistics: (S)

Max	1.490E-06	25%	829.999E-09	SpecHigh	N/A
Mean	1.086E-06	10%	799.999E-09	SpecLow	N/A
Min	769.999E-09	N	90	PctWithinSpec	N/A
Range	719.999E-09	Cp	N/A	PctDefSpec	N/A
StdDev	237.207E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8848	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.405E-06	Skew	0.1848		
75%	1.350E-06	Kurtosis	-1.3933		
Median	1.060E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

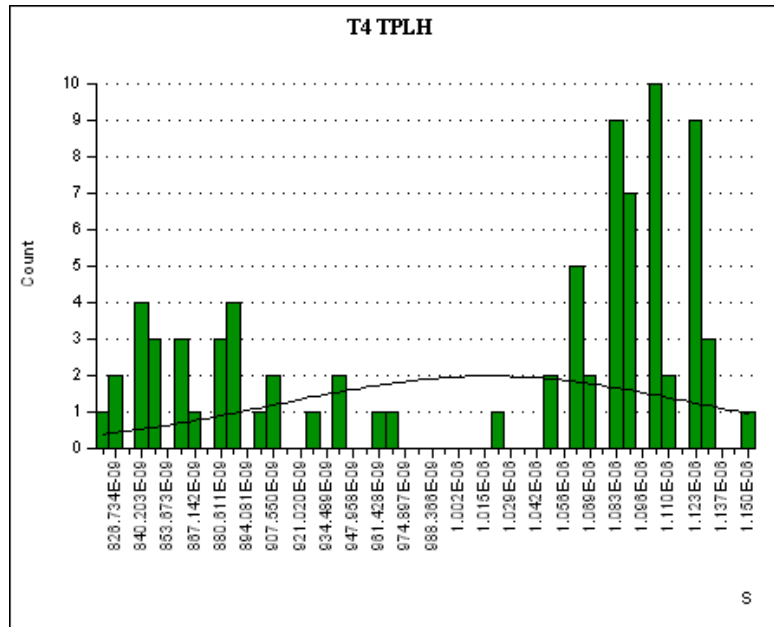
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=9.004, Test.Name=T4 TPLH



Statistics: (S)

Max	1.150E-06	25%	889.999E-09	SpecHigh	N/A
Mean	1.016E-06	10%	849.999E-09	SpecLow	N/A
Min	819.999E-09	N	80	PctWithinSpec	N/A
Range	329.999E-09	Cp	N/A	PctDefSpec	N/A
StdDev	108.100E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8159	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.120E-06	Skew	-0.6176		
75%	1.100E-06	Kurtosis	-1.3507		
Median	1.080E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

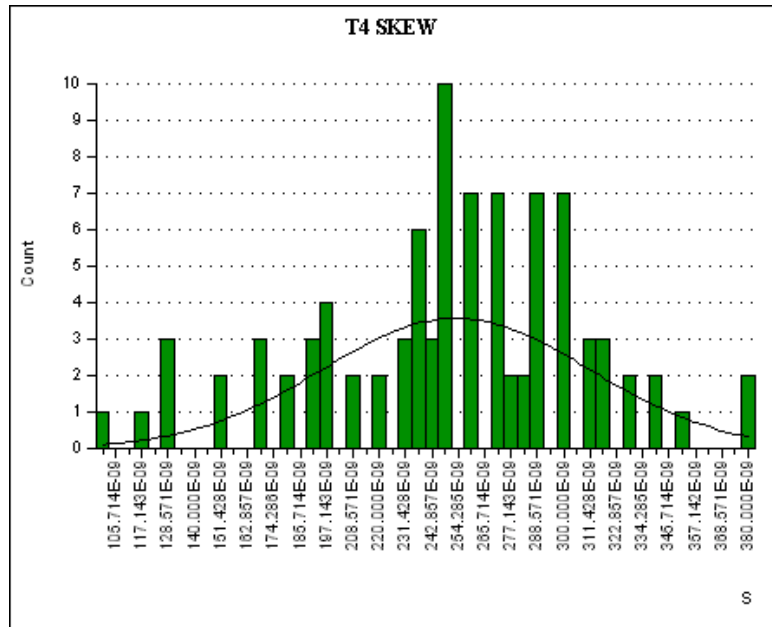
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.005, Test.Name=T4 SKEW



Statistics: (S)

Max	380.000E-09	25%	220.000E-09	SpecHigh	N/A
Mean	251.777E-09	10%	170.000E-09	SpecLow	N/A
Min	100.000E-09	N	90	PctWithinSpec	N/A
Range	280.000E-09	Cp	N/A	PctDefSpec	N/A
StdDev	57.408E-09	Cpl	N/A	NWithinSpec	N/A
W	0.9759	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0927	Cpk	N/A		
90%	319.999E-09	Skew	-0.4166		
75%	290.000E-09	Kurtosis	0.1725		
Median	255.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

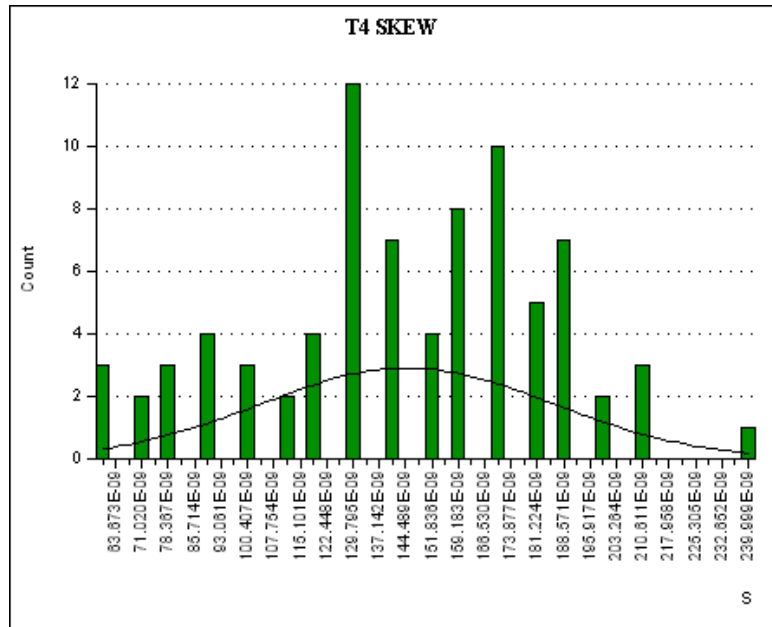
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=9.005, Test.Name=T4 SKEW



Statistics: (S)

Max	239.999E-09	25%	120.000E-09	SpecHigh	N/A
Mean	144.250E-09	10%	85.000E-09	SpecLow	N/A
Min	59.999E-09	N	80	PctWithinSpec	N/A
Range	180.000E-09	Cp	N/A	c	
StdDev	40.214E-09	Cpl	N/A	PctDefSpec	N/A
W	0.9741	Cpu	N/A	NWithinSpec	N/A
WpValue	0.1044	Cpk	N/A	NOutsideSpec	N/A
90%	190.000E-09	Skew	-0.2597		
75%	170.000E-09	Kurtosis	-0.4174		
Median	145.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

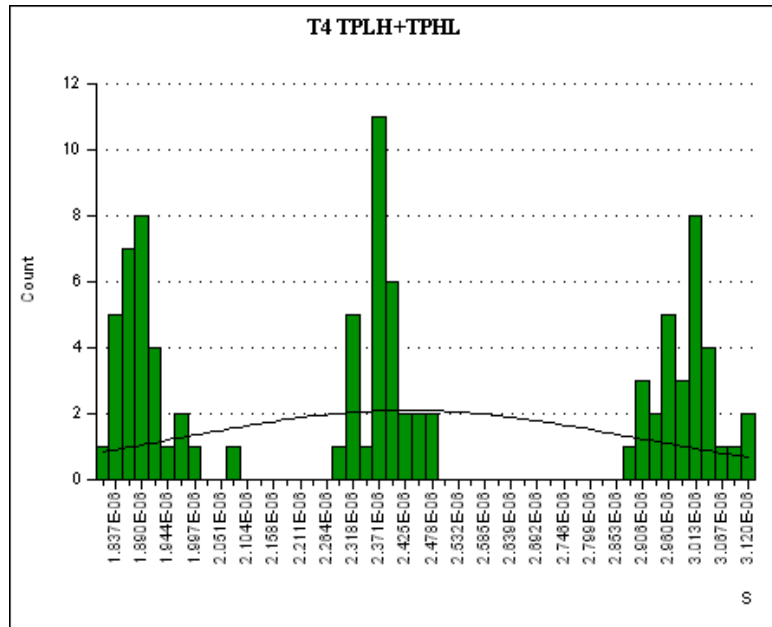
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.006, Test.Name=T4 TPLH+TPHL



Statistics: (S)

Max	3.120E-06	25%	1.910E-06	SpecHigh	N/A
Mean	2.424E-06	10%	1.860E-06	SpecLow	N/A
Min	1.810E-06	N	90	PctWithinSpec	N/A
Range	1.310E-06	Cp	N/A	PctDefSpec	N/A
StdDev	455.654E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8644	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	3.020E-06	Skew	0.1504		
75%	2.960E-06	Kurtosis	-1.4648		
Median	2.375E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

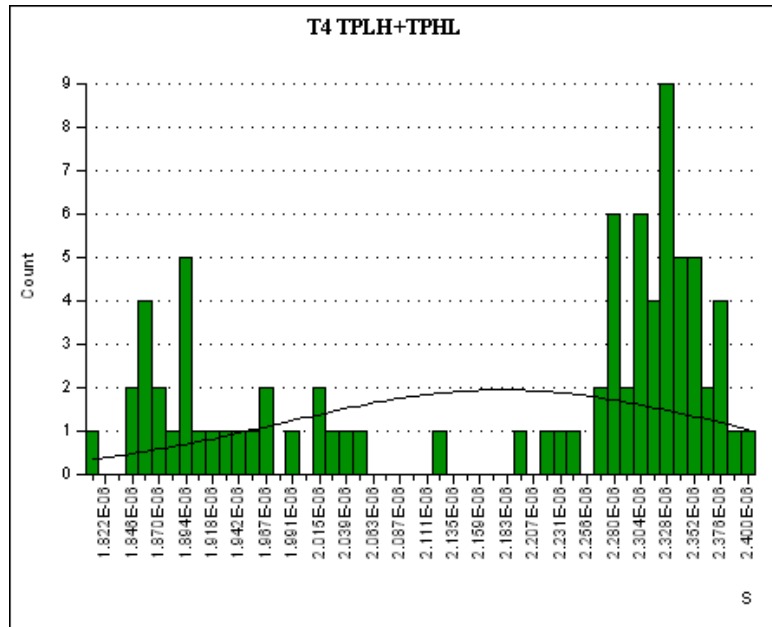
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=9.006, Test.Name=T4 TPLH+TPHL



Statistics: (S)

Max	2.400E-06	25%	1.965E-06	SpecHigh	N/A
Mean	2.175E-06	10%	1.870E-06	SpecLow	N/A
Min	1.810E-06	N	80	PctWithinSpec	N/A
Range	589.999E-09	Cp	N/A	PctDefSpec	N/A
StdDev	196.860E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8028	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	2.355E-06	Skew	-0.6349		
75%	2.330E-06	Kurtosis	-1.3591		
Median	2.280E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

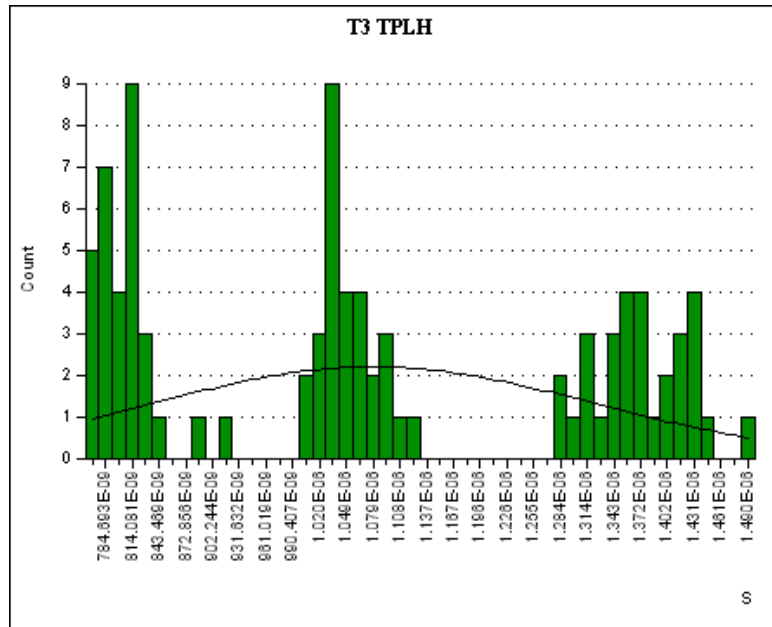
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.007, Test.Name=T3 TPLH



Statistics: (S)

Max	1.490E-06	25%	819.999E-09	SpecHigh	N/A
Mean	1.076E-06	10%	779.999E-09	SpecLow	N/A
Min	769.999E-09	N	90	PctWithinSpec	N/A
Range	719.999E-09	Cp	N/A	PctDefSpec	N/A
StdDev	238.087E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8825	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.405E-06	Skew	0.2014		
75%	1.340E-06	Kurtosis	-1.4161		
Median	1.045E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

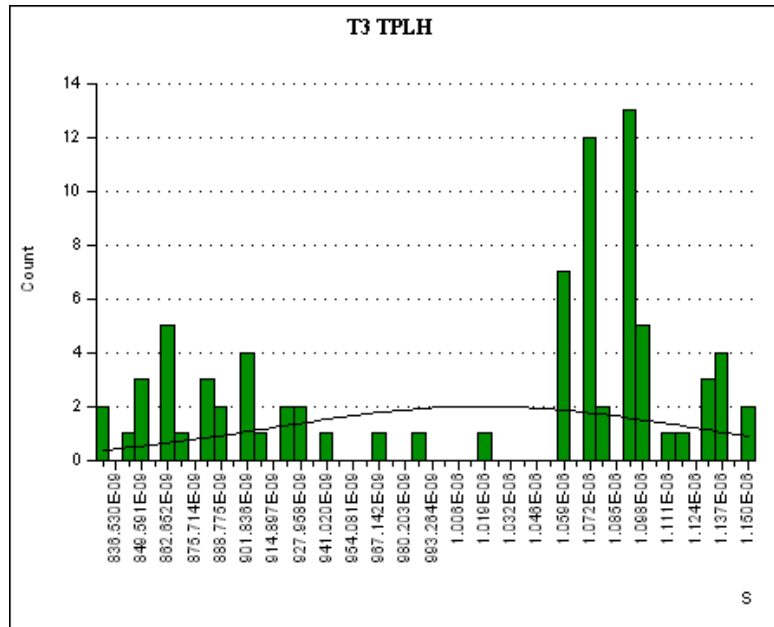
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=9.007, Test.Name=T3 TPLH



Statistics: (S)

Max	1.150E-06	25%	899.999E-09	SpecHigh	N/A
Mean	1.017E-06	10%	859.999E-09	SpecLow	N/A
Min	829.999E-09	N	80	PctWithinSpec	N/A
Range	319.999E-09	Cp	N/A	c	
StdDev	103.064E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8412	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	1.130E-06	Skew	-0.5754		
75%	1.090E-06	Kurtosis	-1.3041		
Median	1.070E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

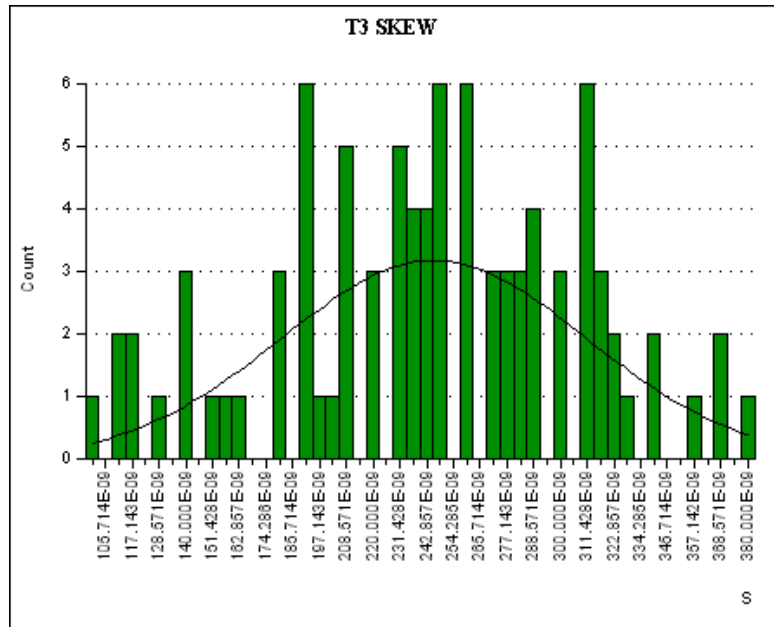
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.008, Test.Name=T3 SKEW



Statistics: (S)

Max	380.000E-09	25%	200.001E-09	SpecHigh	N/A
Mean	244.444E-09	10%	145.000E-09	SpecLow	N/A
Min	100.000E-09	N	90	PctWithinSpec	N/A
Range	280.000E-09	Cp	N/A	PctDefSpec	N/A
StdDev	64.653E-09	Cpl	N/A	NWithinSpec	N/A
W	0.9828	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.2801	Cpk	N/A		
90%	320.000E-09	Skew	-0.2320		
75%	290.000E-09	Kurtosis	-0.3777		
Median	249.999E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

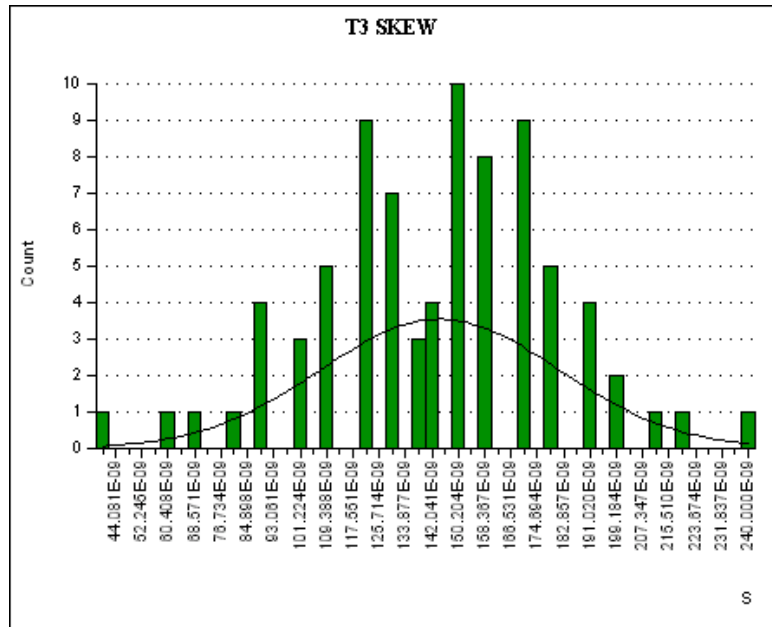
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=9.008, Test.Name=T3 SKEW



Statistics: (S)

Max	240.000E-09	25%	120.000E-09	SpecHigh	N/A
Mean	143.375E-09	10%	95.000E-09	SpecLow	N/A
Min	40.000E-09	N	80	PctWithinSpec	N/A
Range	200.001E-09	Cp	N/A	c	
StdDev	36.697E-09	Cpl	N/A	PctDefSpec	N/A
W	0.9905	Cpu	N/A	NWithinSpec	N/A
WpValue	0.8256	Cpk	N/A	NOutsideSpec	N/A
90%	190.000E-09	Skew	-0.1664		
75%	170.000E-09	Kurtosis	0.3075		
Median	149.999E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

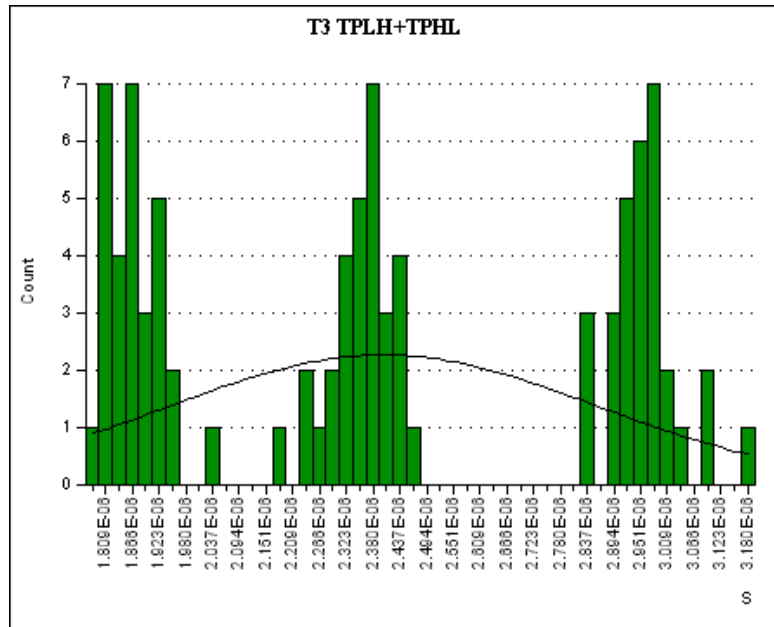
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.009, Test.Name=T3 TPLH+TPHL



Statistics: (S)

Max	3.180E-06	25%	1.910E-06	SpecHigh	N/A
Mean	2.396E-06	10%	1.845E-06	SpecLow	N/A
Min	1.780E-06	N	90	PctWithinSpec	N/A
Range	1.400E-06	Cp	N/A	c	
StdDev	452.327E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8797	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	2.985E-06	Skew	0.1413		
75%	2.910E-06	Kurtosis	-1.4450		
Median	2.365E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

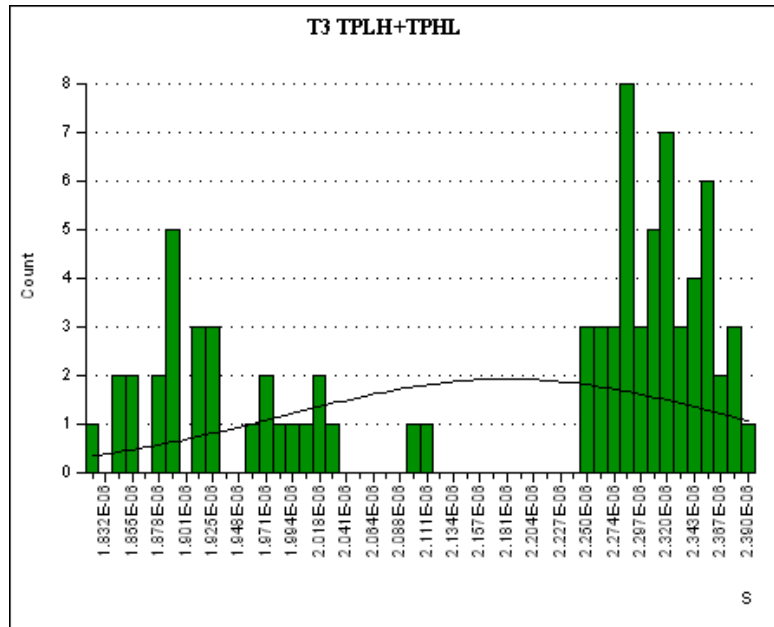
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=9.009, Test.Name=T3 TPLH+TPHL



Statistics: (S)

Max	2.390E-06	25%	1.970E-06	SpecHigh	N/A
Mean	2.177E-06	10%	1.890E-06	SpecLow	N/A
Min	1.820E-06	N	80	PctWithinSpec	N/A
Range	569.999E-09	Cp	N/A	c	
StdDev	192.298E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8039	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	2.360E-06	Skew	-0.6579		
75%	2.320E-06	Kurtosis	-1.3194		
Median	2.280E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

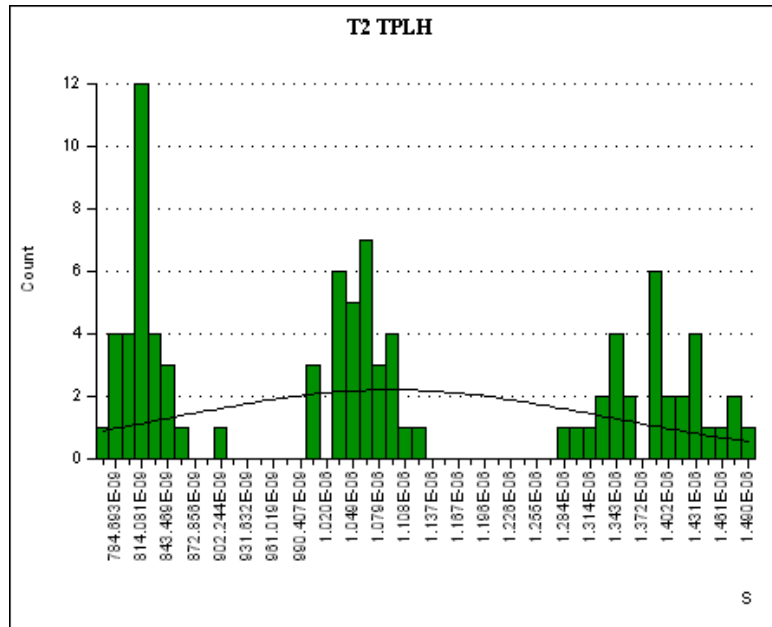
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.010, Test.Name=T2 TPLH



Statistics: (S)

Max	1.490E-06	25%	829.999E-09	SpecHigh	N/A
Mean	1.089E-06	10%	804.999E-09	SpecLow	N/A
Min	769.999E-09	N	90	PctWithinSpec	N/A
Range	719.999E-09	Cp	N/A	PctDefSpec	N/A
StdDev	238.645E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8811	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.420E-06	Skew	0.2243		
75%	1.350E-06	Kurtosis	-1.4027		
Median	1.060E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

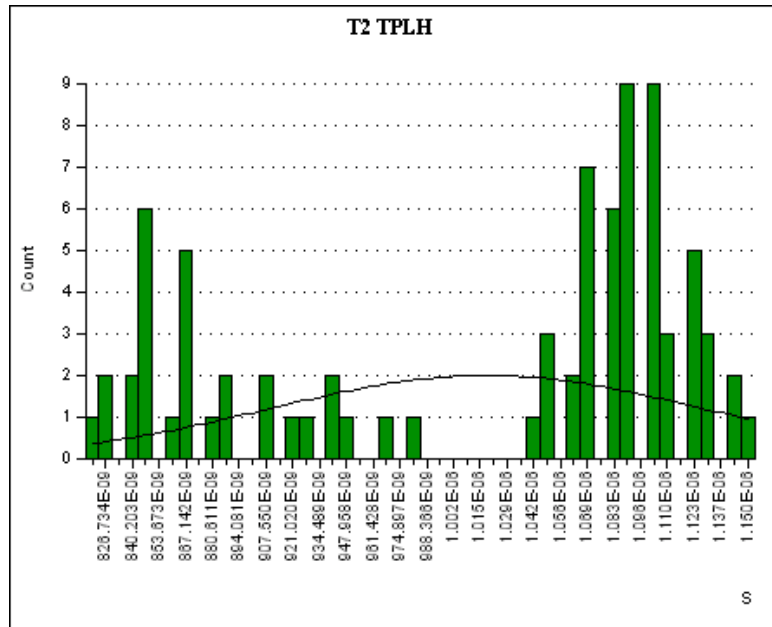
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=9.010, Test.Name=T2 TPLH



Statistics: (S)

Max	1.150E-06	25%	899.999E-09	SpecHigh	N/A
Mean	1.016E-06	10%	849.999E-09	SpecLow	N/A
Min	819.999E-09	N	80	PctWithinSpec	N/A
Range	329.999E-09	Cp	N/A	c	
StdDev	107.233E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8239	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	1.120E-06	Skew	-0.6366		
75%	1.100E-06	Kurtosis	-1.2924		
Median	1.070E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

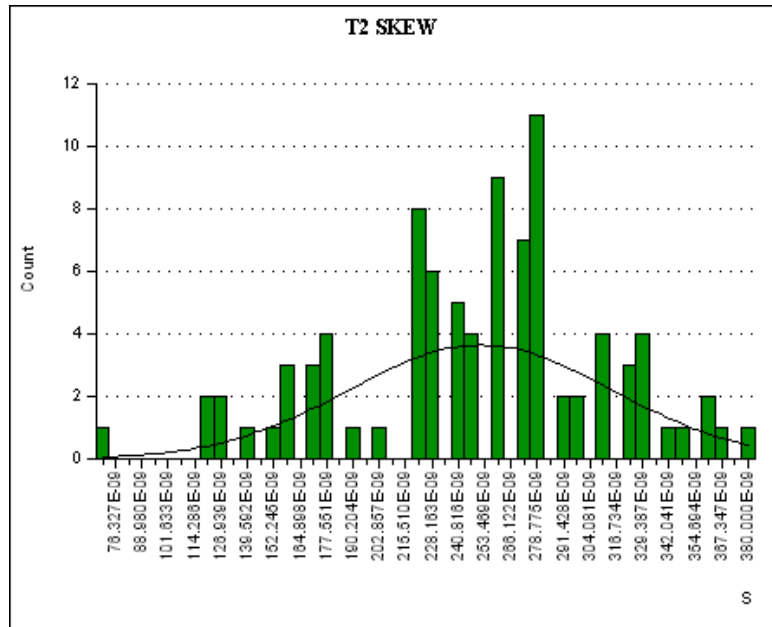
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.011, Test.Name=T2 SKEW



Statistics: (S)

Max	380.000E-09	25%	219.999E-09	SpecHigh	N/A
Mean	249.666E-09	10%	160.000E-09	SpecLow	N/A
Min	70.000E-09	N	90	PctWithinSpec	N/A
Range	309.999E-09	Cp	N/A	PctDefSpec	N/A
StdDev	62.395E-09	Cpl	N/A	NWithinSpec	N/A
W	0.9784	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.1390	Cpk	N/A		
90%	329.999E-09	Skew	-0.3962		
75%	280.000E-09	Kurtosis	0.0524		
Median	259.999E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

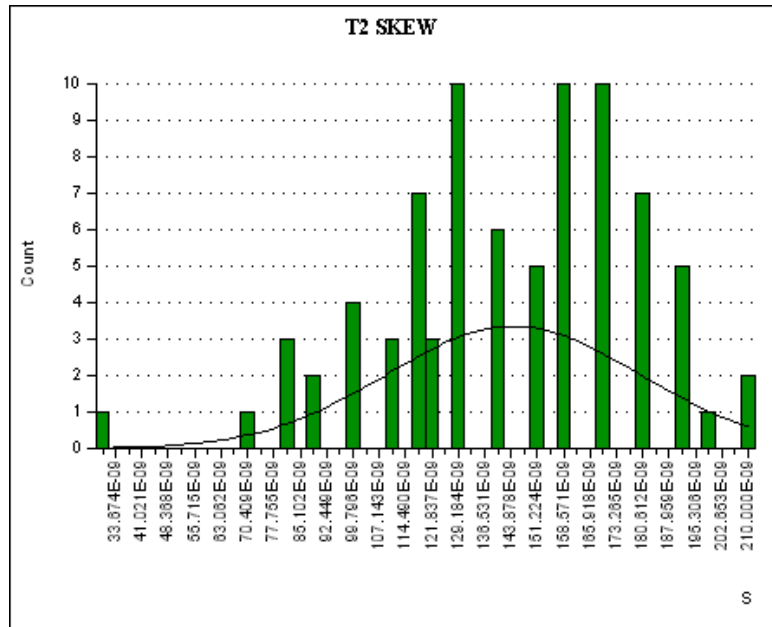
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=9.011, Test.Name=T2 SKEW



Statistics: (S)

Max	210.000E-09	25%	120.000E-09	SpecHigh	N/A
Mean	143.375E-09	10%	100.000E-09	SpecLow	N/A
Min	30.001E-09	N	80	PctWithinSpec	N/A
Range	179.999E-09	Cp	N/A	PctDefSpec	N/A
StdDev	34.966E-09	Cpl	N/A	NWithinSpec	N/A
W	0.9712	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0679	Cpk	N/A		
90%	184.999E-09	Skew	-0.5011		
75%	170.000E-09	Kurtosis	0.2788		
Median	145.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

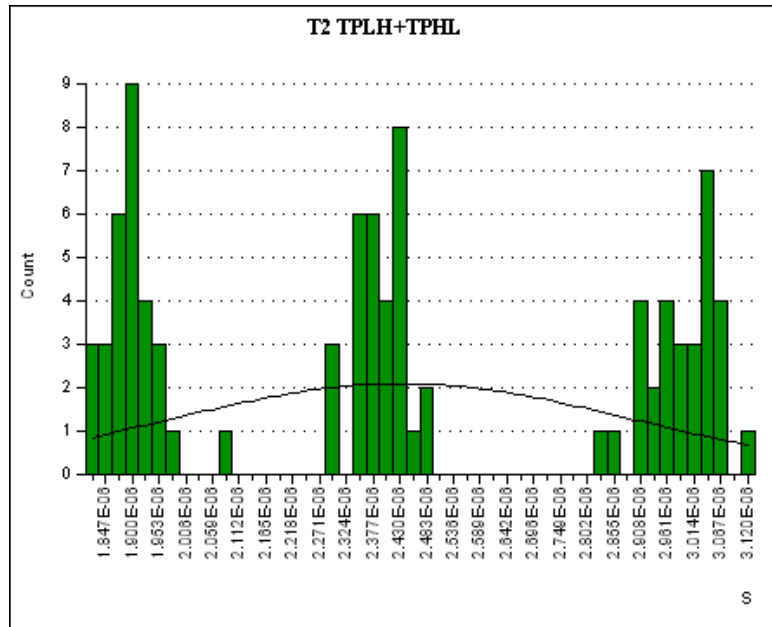
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.012, Test.Name=T2 TPLH+TPHL



Statistics: (S)

Max	3.120E-06	25%	1.920E-06	SpecHigh	N/A
Mean	2.427E-06	10%	1.870E-06	SpecLow	N/A
Min	1.820E-06	N	90	PctWithinSpec	N/A
Range	1.300E-06	Cp	N/A	PctDefSpec	N/A
StdDev	453.842E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8674	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	3.035E-06	Skew	0.1321		
75%	2.940E-06	Kurtosis	-1.4595		
Median	2.395E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

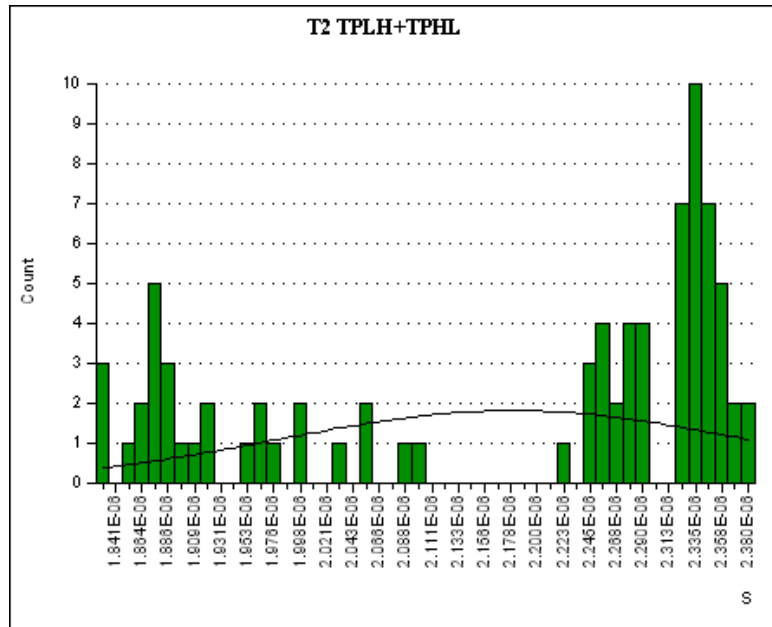
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=9.012, Test.Name=T2 TPLH+TPHL



Statistics: (S)

Max	2.380E-06	25%	1.965E-06	SpecHigh	N/A
Mean	2.176E-06	10%	1.870E-06	SpecLow	N/A
Min	1.830E-06	N	80	PctWithinSpec	N/A
Range	550.000E-09	Cp	N/A	PctDefSpec	N/A
StdDev	196.670E-09	Cpl	N/A	NWithinSpec	N/A
W	0.7975	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	2.360E-06	Skew	-0.6635		
75%	2.340E-06	Kurtosis	-1.3133		
Median	2.280E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

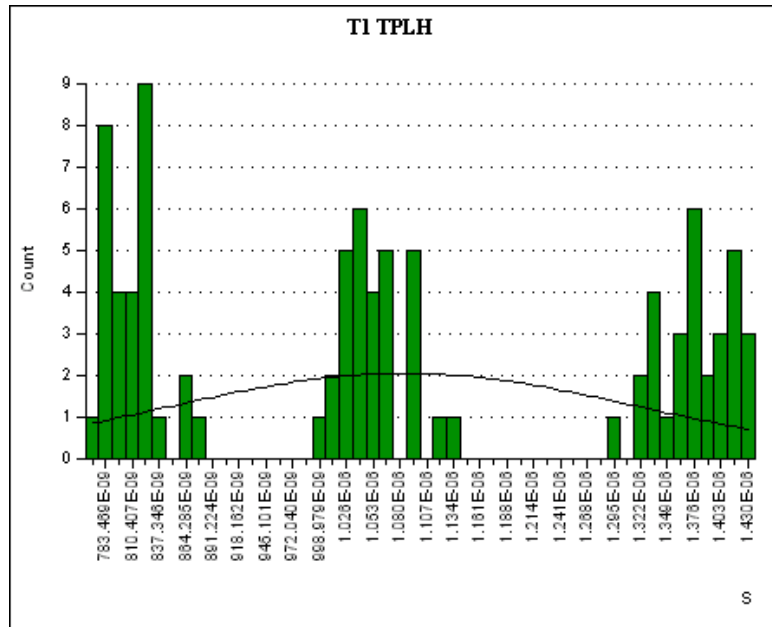
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.013, Test.Name=T1 TPLH



Statistics: (S)

Max	1.430E-06	25%	819.999E-09	SpecHigh	N/A
Mean	1.081E-06	10%	794.999E-09	SpecLow	N/A
Min	769.999E-09	N	90	PctWithinSpec	N/A
Range	659.999E-09	Cp	N/A	c	
StdDev	235.026E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8669	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	1.400E-06	Skew	0.1909		
75%	1.350E-06	Kurtosis	-1.4618		
Median	1.050E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

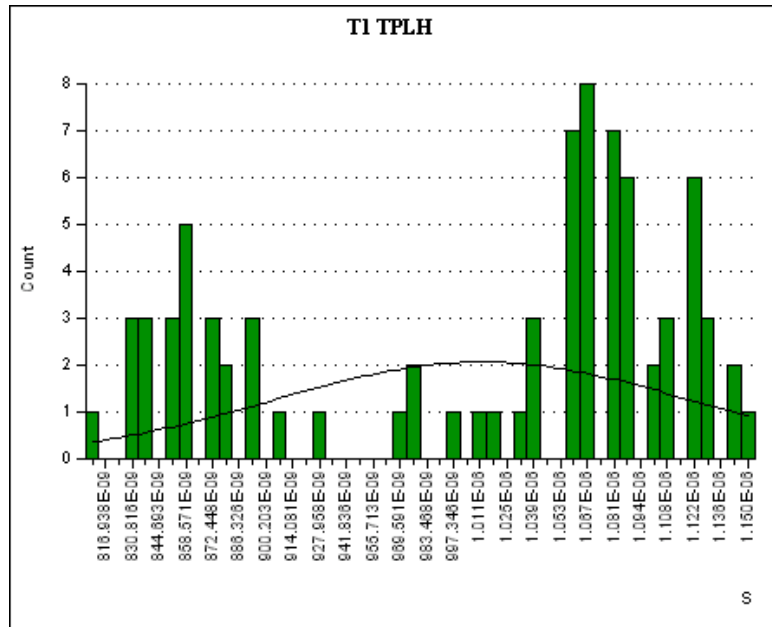
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=9.013, Test.Name=T1 TPLH



Statistics: (S)

Max	1.150E-06	25%	884.999E-09	SpecHigh	N/A
Mean	1.010E-06	10%	849.999E-09	SpecLow	N/A
Min	809.999E-09	N	80	PctWithinSpec	N/A
Range	339.999E-09	Cp	N/A	c	
StdDev	107.120E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8465	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	1.120E-06	Skew	-0.5941		
75%	1.090E-06	Kurtosis	-1.2792		
Median	1.060E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

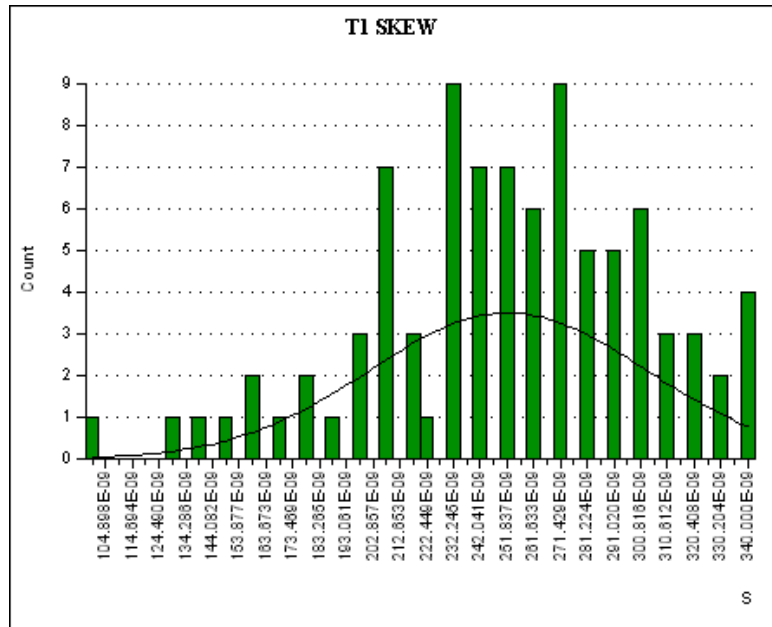
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.014, Test.Name=T1 SKEW



Statistics: (S)

Max	340.000E-09	25%	220.000E-09	SpecHigh	N/A
Mean	250.666E-09	10%	185.000E-09	SpecLow	N/A
Min	100.000E-09	N	90	PctWithinSpec	N/A
Range	240.000E-09	Cp	N/A	c	
StdDev	50.164E-09	Cpl	N/A	PctDefSpec	N/A
W	0.9782	Cpu	N/A	NWithinSpec	N/A
WpValue	0.1356	Cpk	N/A	NOutsideSpec	N/A
90%	315.000E-09	Skew	-0.4428		
75%	289.999E-09	Kurtosis	0.2333		
Median	250.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

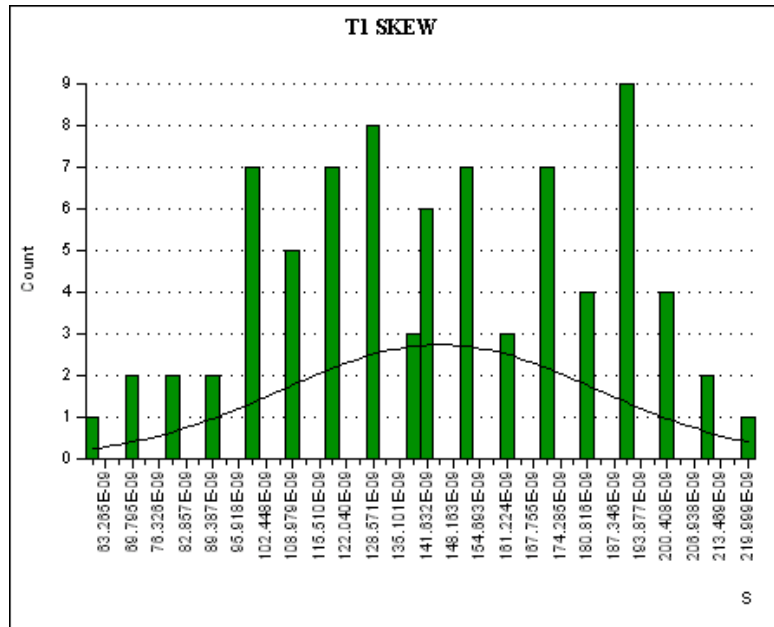
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=9.014, Test.Name=T1 SKEW



Statistics: (S)

Max	219.999E-09	25%	120.000E-09	SpecHigh	N/A
Mean	144.000E-09	10%	100.000E-09	SpecLow	N/A
Min	59.999E-09	N	80	PctWithinSpec	N/A
Range	160.000E-09	Cp	N/A	c	
StdDev	38.007E-09	Cpl	N/A	PctDefSpec	N/A
W	0.9754	Cpu	N/A	NWithinSpec	N/A
WpValue	0.1261	Cpk	N/A	NOutsideSpec	N/A
90%	190.000E-09	Skew	-0.0564		
75%	175.000E-09	Kurtosis	-0.7813		
Median	140.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

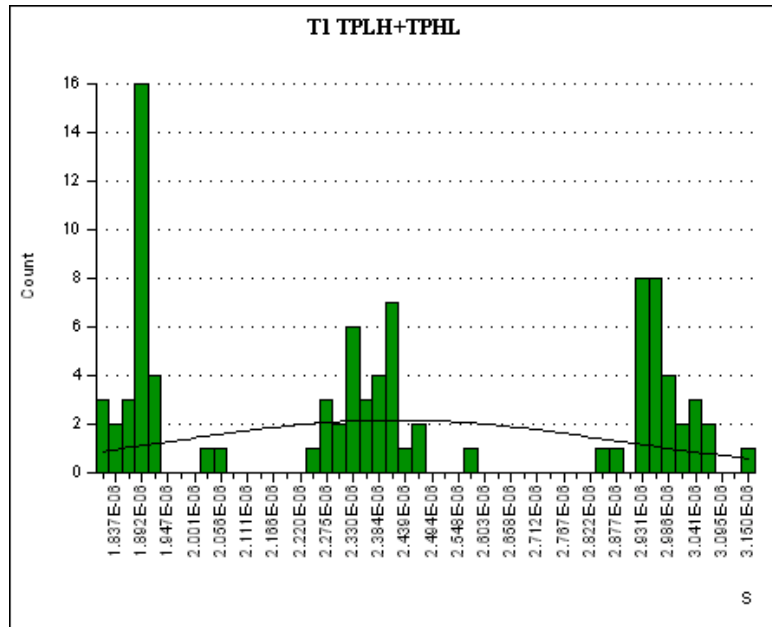
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.015, Test.Name=T1 TPLH+TPHL



Statistics: (S)

Max	3.150E-06	25%	1.900E-06	SpecHigh	N/A
Mean	2.412E-06	10%	1.880E-06	SpecLow	N/A
Min	1.810E-06	N	90	PctWithinSpec	N/A
Range	1.340E-06	Cp	N/A	PctDefSpec	N/A
StdDev	450.725E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8680	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	2.990E-06	Skew	0.1449		
75%	2.940E-06	Kurtosis	-1.4752		
Median	2.375E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

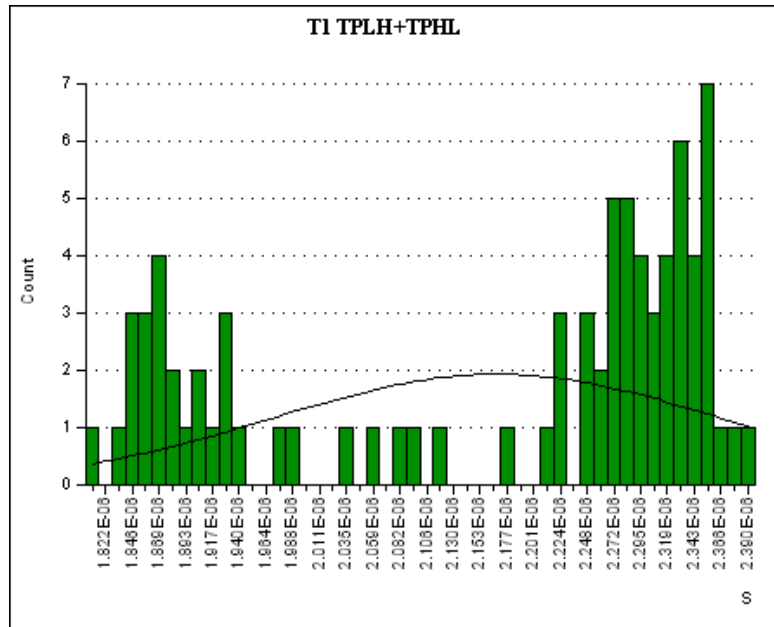
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=9.015, Test.Name=T1 TPLH+TPHL



Statistics: (S)

Max	2.390E-06	25%	1.930E-06	SpecHigh	N/A
Mean	2.164E-06	10%	1.865E-06	SpecLow	N/A
Min	1.810E-06	N	80	PctWithinSpec	N/A
Range	579.999E-09	Cp	N/A	PctDefSpec	N/A
StdDev	195.414E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8130	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	2.350E-06	Skew	-0.6477		
75%	2.325E-06	Kurtosis	-1.3114		
Median	2.270E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

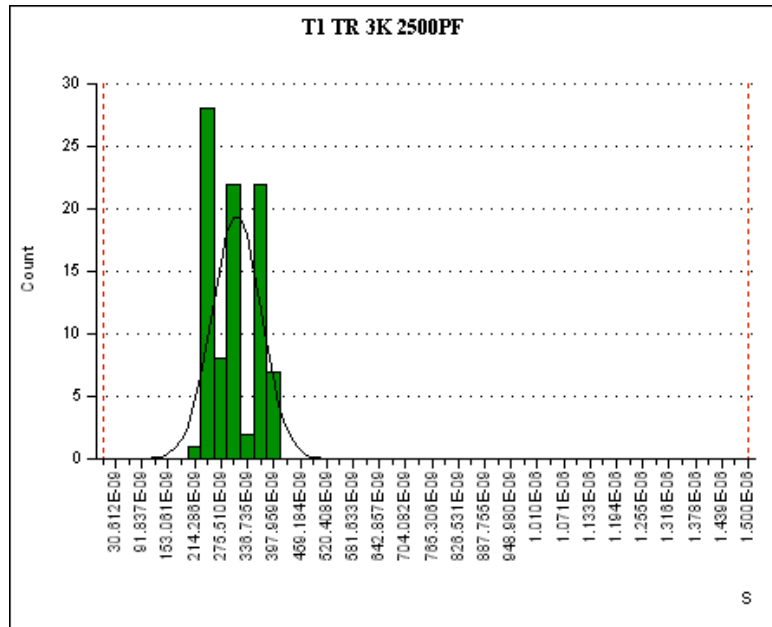
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=10.000, Test.Name=T1 TR 3K 2500PF



Statistics: (S)

Max	400.000E-09	25%	250.000E-09	SpecHigh	1.500E-06
Mean	307.333E-09	10%	240.000E-09	SpecLow	0
Min	220.000E-09	N	90	PctWithinSpec	100.00
Range	180.000E-09	Cp	>4.0000	PctDefSpec	0
StdDev	56.366E-09	Cpl	1.8175	NWithinSpec	90
W	0.8982	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	1.8175		
90%	380.000E-09	Skew	0.1183		
75%	370.000E-09	Kurtosis	-1.4095		
Median	300.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

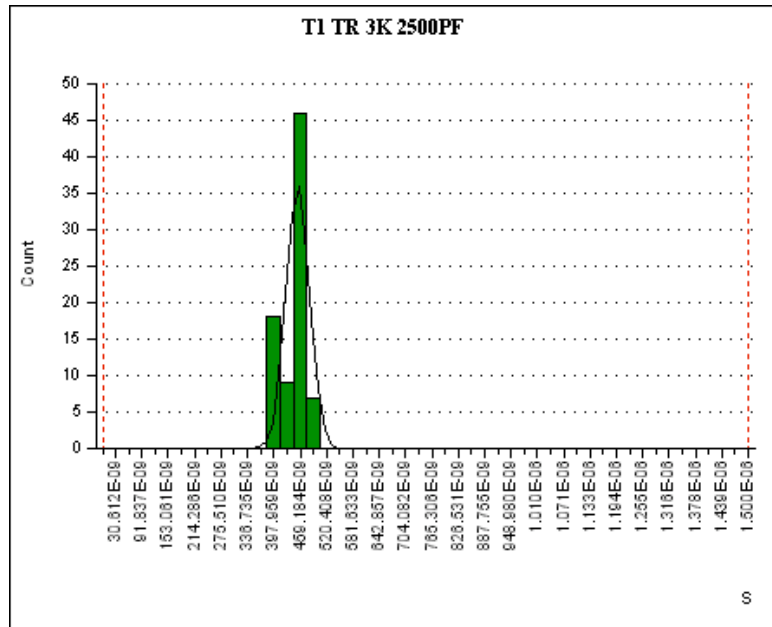
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=10.000, Test.Name=T1 TR 3K 2500PF



Statistics: (S)

Max	490.000E-09	25%	425.000E-09	SpecHigh	1.500E-06
Mean	448.000E-09	10%	410.000E-09	SpecLow	0
Min	390.000E-09	N	80	PctWithinSpec	100.00
Range	100.000E-09	Cp	>4.0000	c	
StdDev	27.068E-09	Cpl	>4.0000	PctDefSpec	0
W	0.8781	Cpu	>4.0000	NWithinSpec	80
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	470.000E-09	Skew	-0.6547		
75%	470.000E-09	Kurtosis	-0.8940		
Median	460.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

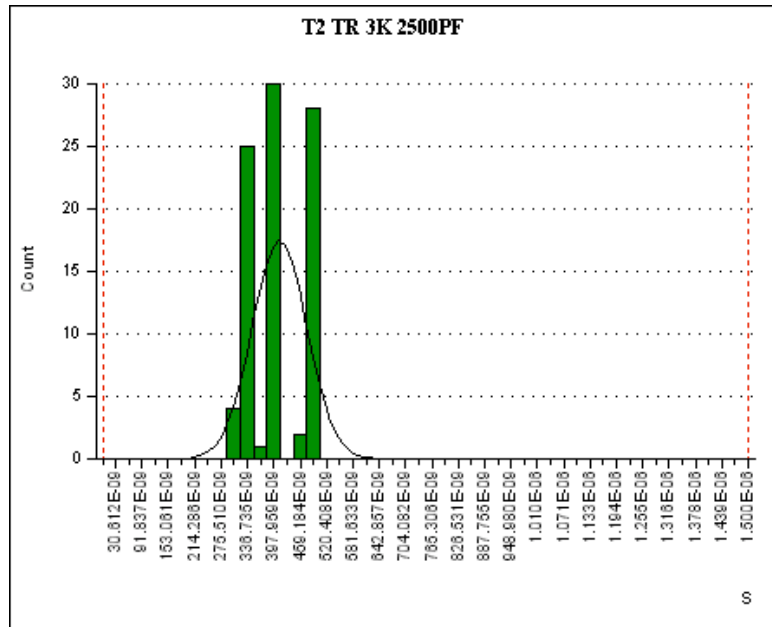
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=10.001, Test.Name=T2 TR 3K 2500PF



Statistics: (S)

Max	500.000E-09	25%	340.000E-09	SpecHigh	1.500E-06
Mean	406.000E-09	10%	330.000E-09	SpecLow	0
Min	310.000E-09	N	90	PctWithinSpec	100.00
Range	190.000E-09	Cp	3.9766	PctDefSpec	0
StdDev	62.868E-09	Cpl	2.1527	NWithinSpec	90
W	0.8694	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	2.1527		
90%	490.000E-09	Skew	0.1794		
75%	480.000E-09	Kurtosis	-1.4383		
Median	399.999E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

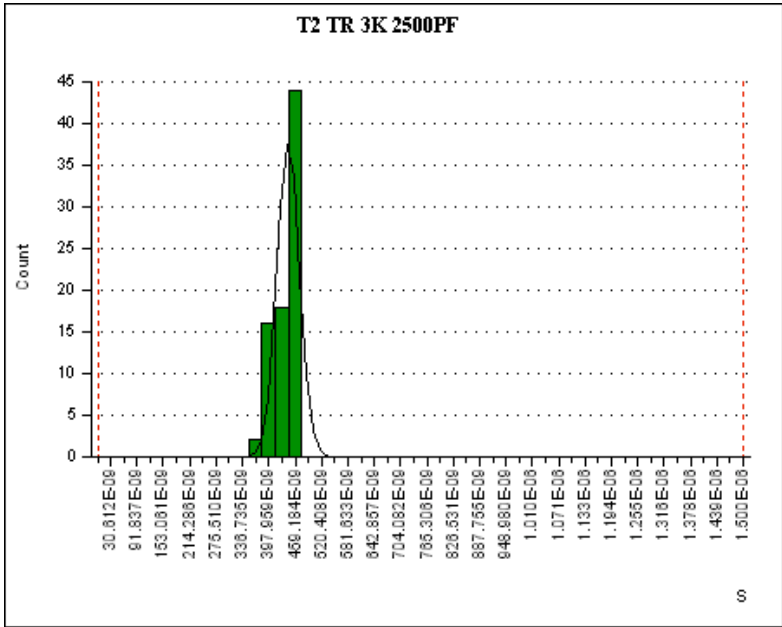
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=10.001, Test.Name=T2 TR 3K 2500PF



Statistics: (S)

Max	470.000E-09	25%	420.000E-09	SpecHigh	1.500E-06
Mean	437.500E-09	10%	395.000E-09	SpecLow	0
Min	380.000E-09	N	80	PctWithinSpec	100.00
Range	90.000E-09	Cp	>4.0000	c	
StdDev	25.877E-09	Cpl	>4.0000	PctDefSpec	0
W	0.8909	Cpu	>4.0000	NWithinSpec	80
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	465.000E-09	Skew	-0.6833		
75%	460.000E-09	Kurtosis	-0.7382		
Median	450.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

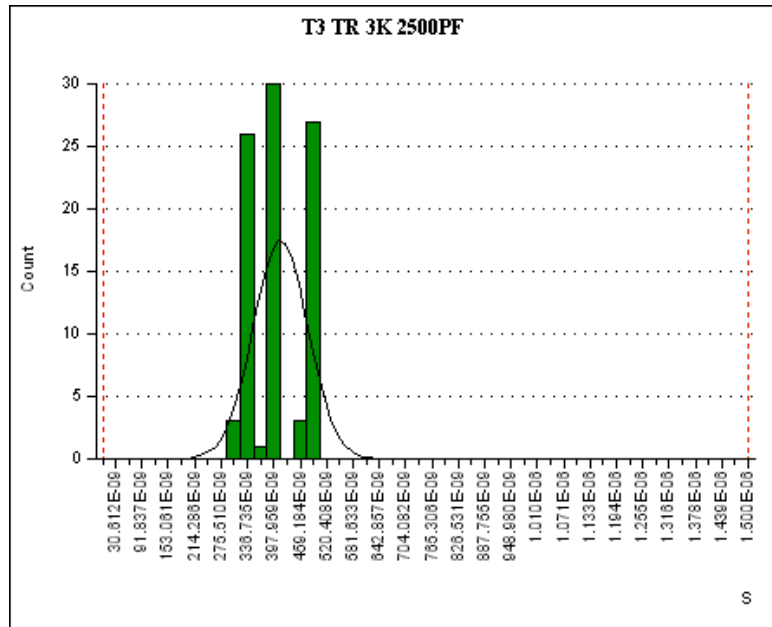
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=10.002, Test.Name=T3 TR 3K 2500PF



Statistics: (S)

Max	500.000E-09	25%	340.000E-09	SpecHigh	1.500E-06
Mean	408.222E-09	10%	330.000E-09	SpecLow	0
Min	320.000E-09	N	90	PctWithinSpec	100.00
Range	180.000E-09	Cp	3.9757	PctDefSpec	0
StdDev	62.882E-09	Cpl	2.1640	NWithinSpec	90
W	0.8686	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	2.1640		
90%	490.000E-09	Skew	0.1884		
75%	480.000E-09	Kurtosis	-1.4180		
Median	399.999E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

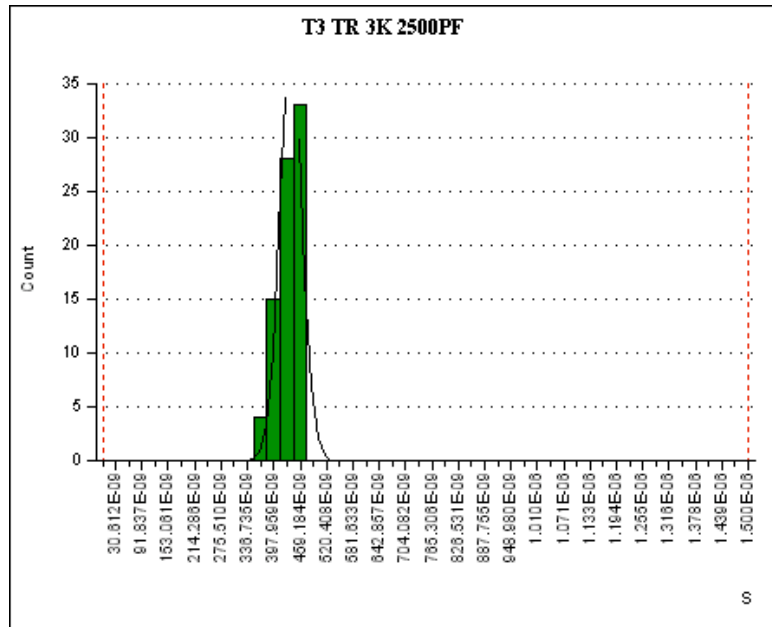
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=10.002, Test.Name=T3 TR 3K 2500PF



Statistics: (S)

Max	470.000E-09	25%	420.000E-09	SpecHigh	1.500E-06
Mean	432.250E-09	10%	390.000E-09	SpecLow	0
Min	370.000E-09	N	80	PctWithinSpec	100.00
Range	100.000E-09	Cp	>4.0000	c	
StdDev	25.949E-09	Cpl	>4.0000	PctDefSpec	0
W	0.9057	Cpu	>4.0000	NWithinSpec	80
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	460.000E-09	Skew	-0.6910		
75%	450.000E-09	Kurtosis	-0.5983		
Median	440.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

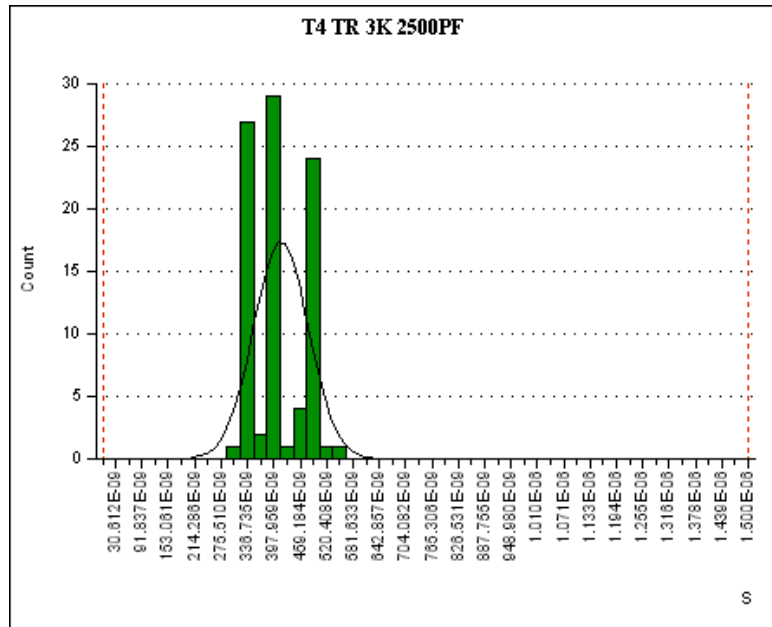
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=10.003, Test.Name=T4 TR 3K 2500PF



Statistics: (S)

Max	539.999E-09	25%	340.000E-09	SpecHigh	1.500E-06
Mean	409.333E-09	10%	330.000E-09	SpecLow	0
Min	320.000E-09	N	90	PctWithinSpec	100.00
Range	220.000E-09	Cp	3.9609	PctDefSpec	0
StdDev	63.117E-09	Cpl	2.1618	NWithinSpec	90
W	0.8884	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	2.1618		
90%	490.000E-09	Skew	0.2191		
75%	480.000E-09	Kurtosis	-1.3380		
Median	399.999E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

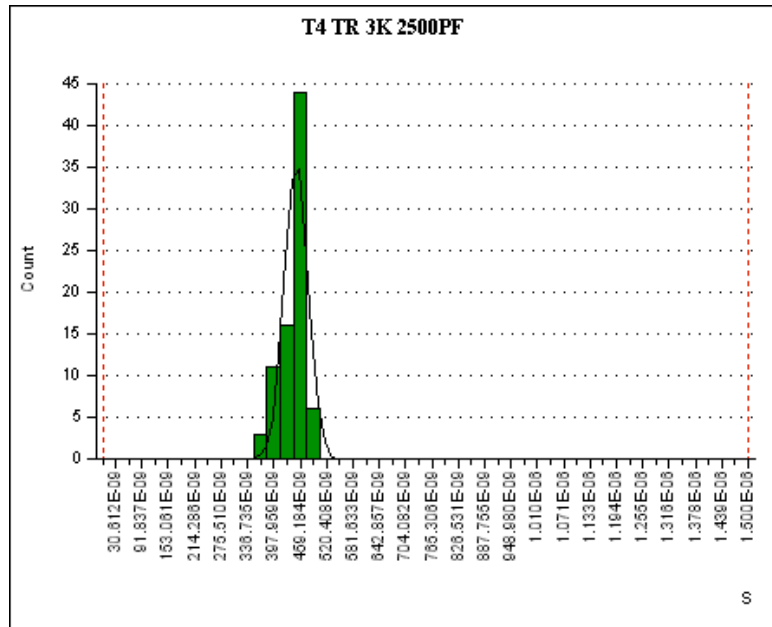
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=10.003, Test.Name=T4 TR 3K 2500PF



Statistics: (S)

Max	490.000E-09	25%	425.000E-09	SpecHigh	1.500E-06
Mean	444.375E-09	10%	400.000E-09	SpecLow	0
Min	380.000E-09	N	80	PctWithinSpec	100.00
Range	110.000E-09	Cp	>4.0000	c	
StdDev	27.460E-09	Cpl	>4.0000	PctDefSpec	0
W	0.9000	Cpu	>4.0000	NWithinSpec	80
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	470.000E-09	Skew	-0.7960		
75%	460.000E-09	Kurtosis	-0.3076		
Median	460.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

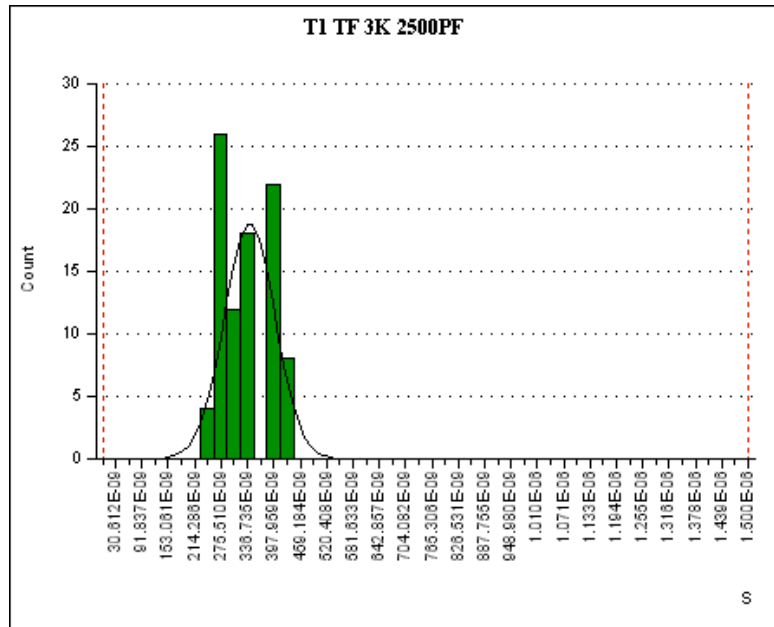
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=10.004, Test.Name=T1 TF 3K 2500PF



Statistics: (S)

Max	440.000E-09	25%	280.000E-09	SpecHigh	1.500E-06
Mean	337.111E-09	10%	270.000E-09	SpecLow	0
Min	260.000E-09	N	90	PctWithinSpec	100.00
Range	180.000E-09	Cp	>4.0000	PctDefSpec	0
StdDev	58.141E-09	Cpl	1.9327	NWithinSpec	90
W	0.8599	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	1.9327		
90%	410.000E-09	Skew	0.3030		
75%	410.000E-09	Kurtosis	-1.4268		
Median	330.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

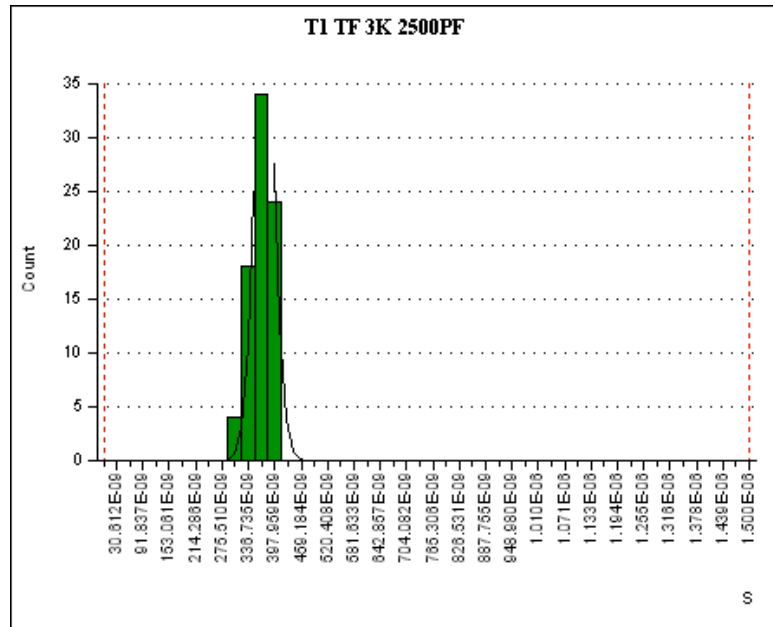
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=10.004, Test.Name=T1 TF 3K 2500PF



Statistics: (S)

Max	400.000E-09	25%	350.000E-09	SpecHigh	1.500E-06
Mean	368.750E-09	10%	330.000E-09	SpecLow	0
Min	320.000E-09	N	80	PctWithinSpec	100.00
Range	80.000E-09	Cp	>4.0000	c	
StdDev	23.566E-09	Cpl	>4.0000	PctDefSpec	0
W	0.9066	Cpu	>4.0000	NWithinSpec	80
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	395.000E-09	Skew	-0.5905		
75%	390.000E-09	Kurtosis	-0.8038		
Median	375.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

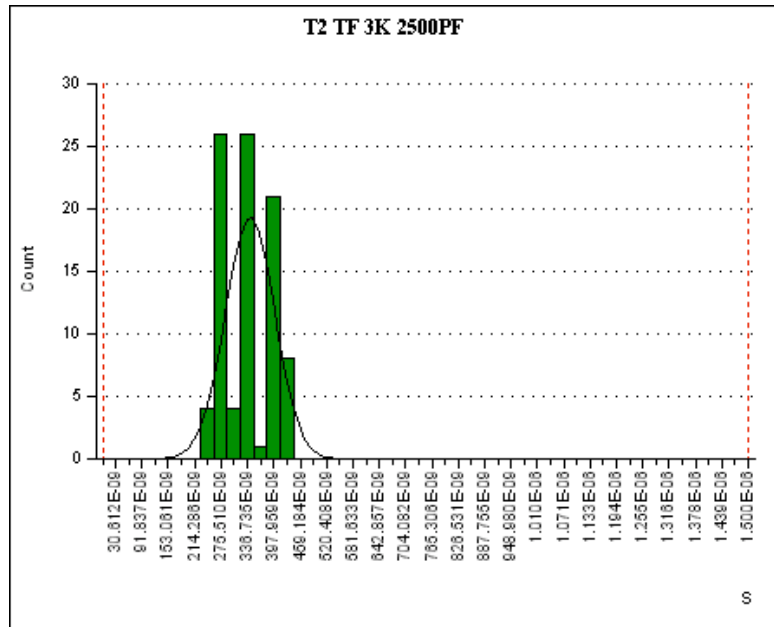
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=10.005, Test.Name=T2 TF 3K 2500PF



Statistics: (S)

Max	420.000E-09	25%	280.000E-09	SpecHigh	1.500E-06
Mean	338.111E-09	10%	270.000E-09	SpecLow	0
Min	260.000E-09	N	90	PctWithinSpec	100.00
Range	160.000E-09	Cp	>4.0000	PctDefSpec	0
StdDev	56.685E-09	Cpl	1.9882	NWithinSpec	90
W	0.8591	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	1.9882		
90%	410.000E-09	Skew	0.2201		
75%	410.000E-09	Kurtosis	-1.4446		
Median	330.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

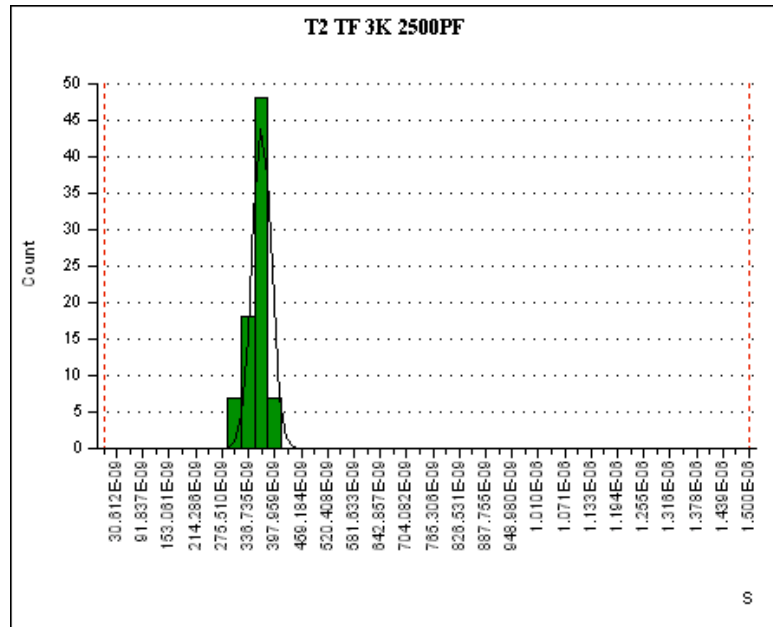
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=10.005, Test.Name=T2 TF 3K 2500PF



Statistics: (S)

Max	400.000E-09	25%	350.000E-09	SpecHigh	1.500E-06
Mean	362.375E-09	10%	330.000E-09	SpecLow	0
Min	310.000E-09	N	80	PctWithinSpec	100.00
Range	90.000E-09	Cp	>4.0000	c	
StdDev	22.233E-09	Cpl	>4.0000	PctDefSpec	0
W	0.8882	Cpu	>4.0000	NWithinSpec	80
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	380.000E-09	Skew	-0.7257		
75%	380.000E-09	Kurtosis	-0.6253		
Median	370.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

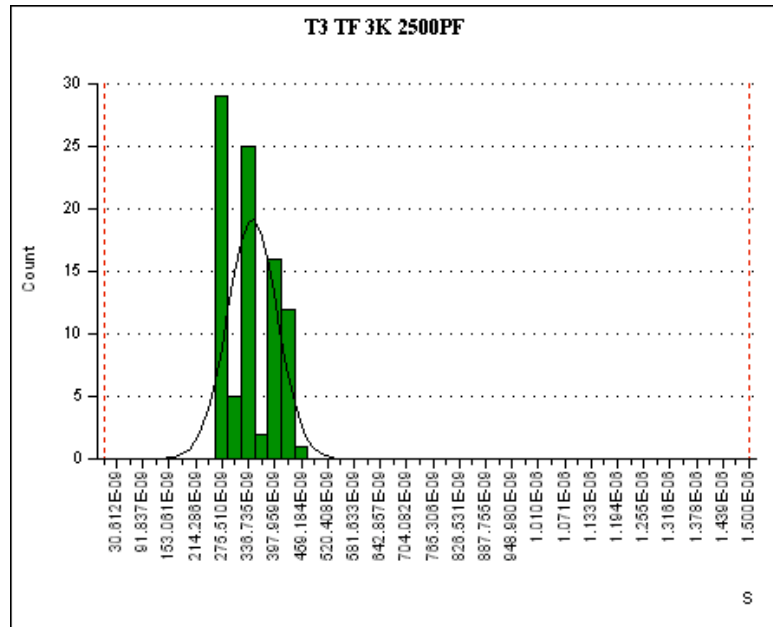
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=10.006, Test.Name=T3 TF 3K 2500PF



Statistics: (S)

Max	470.000E-09	25%	280.000E-09	SpecHigh	1.500E-06
Mean	341.000E-09	10%	275.000E-09	SpecLow	0
Min	270.000E-09	N	90	PctWithinSpec	100.00
Range	200.000E-09	Cp	>4.0000	PctDefSpec	0
StdDev	57.024E-09	Cpl	1.9933	NWithinSpec	90
W	0.8726	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	1.9933		
90%	420.000E-09	Skew	0.3334		
75%	410.000E-09	Kurtosis	-1.2968		
Median	330.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

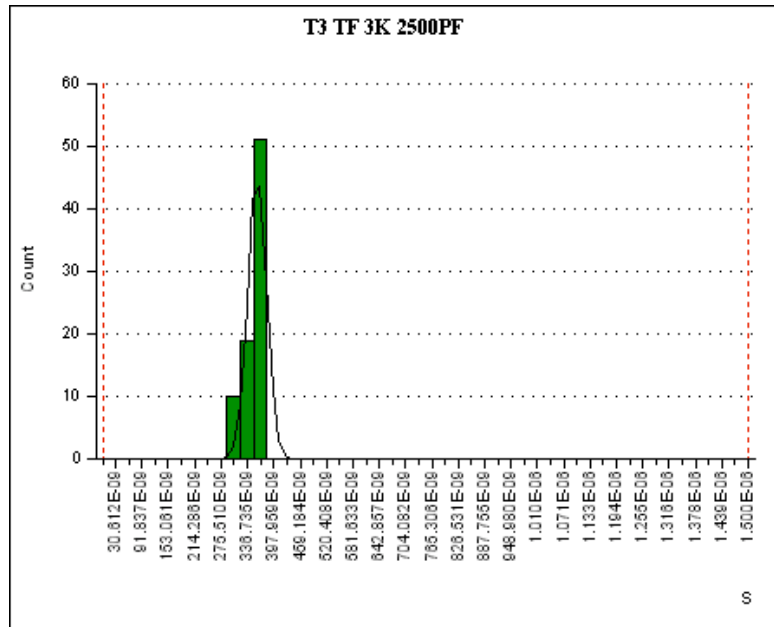
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=10.006, Test.Name=T3 TF 3K 2500PF



Statistics: (S)

Max	380.000E-09	25%	340.000E-09	SpecHigh	1.500E-06
Mean	354.000E-09	10%	320.000E-09	SpecLow	0
Min	300.000E-09	N	80	PctWithinSpec	100.00
Range	80.000E-09	Cp	>4.0000	PctDefSpec	0
StdDev	21.559E-09	Cpl	>4.0000	NWithinSpec	80
W	0.8932	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	380.000E-09	Skew	-0.7459		
75%	370.000E-09	Kurtosis	-0.4329		
Median	360.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

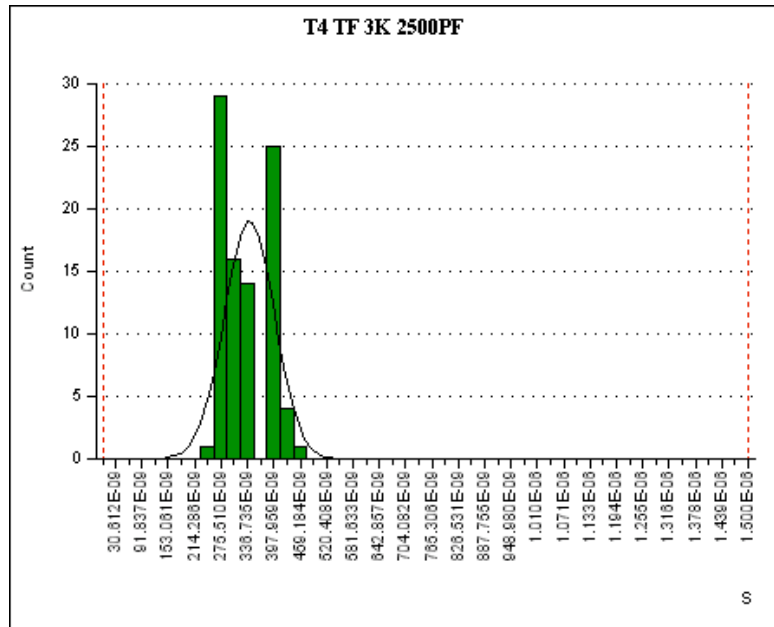
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=10.007, Test.Name=T4 TF 3K 2500PF



Statistics: (S)

Max	470.000E-09	25%	280.000E-09	SpecHigh	1.500E-06
Mean	336.666E-09	10%	270.000E-09	SpecLow	0
Min	260.000E-09	N	90	PctWithinSpec	100.00
Range	210.000E-09	Cp	>4.0000	PctDefSpec	0
StdDev	57.514E-09	Cpl	1.9512	NWithinSpec	90
W	0.8628	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	1.9512		
90%	410.000E-09	Skew	0.3755		
75%	400.000E-09	Kurtosis	-1.2732		
Median	320.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

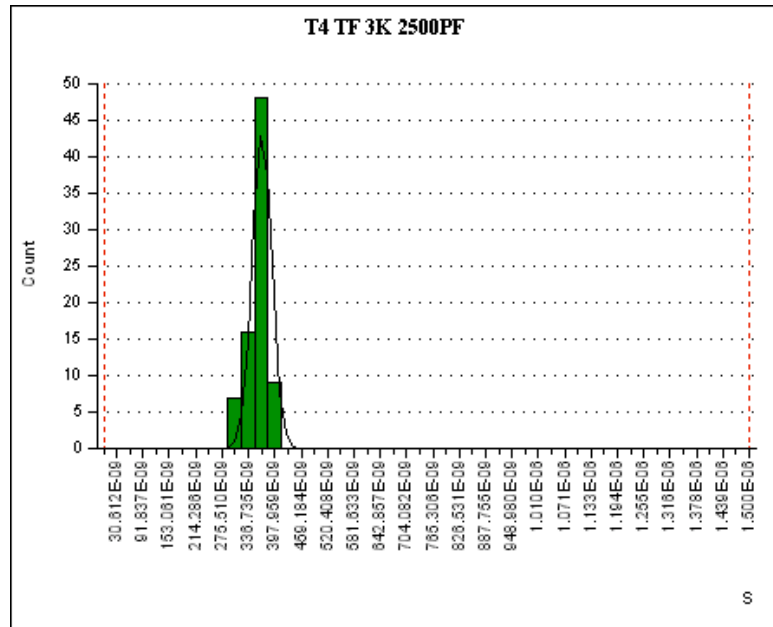
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=10.007, Test.Name=T4 TF 3K 2500PF



Statistics: (S)

Max	400.000E-09	25%	350.000E-09	SpecHigh	1.500E-06
Mean	363.000E-09	10%	330.000E-09	SpecLow	0
Min	320.000E-09	N	80	PctWithinSpec	100.00
Range	80.000E-09	Cp	>4.0000	c	
StdDev	22.580E-09	Cpl	>4.0000	PctDefSpec	0
W	0.8727	Cpu	>4.0000	NWithinSpec	80
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	390.000E-09	Skew	-0.7022		
75%	380.000E-09	Kurtosis	-0.7770		
Median	370.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

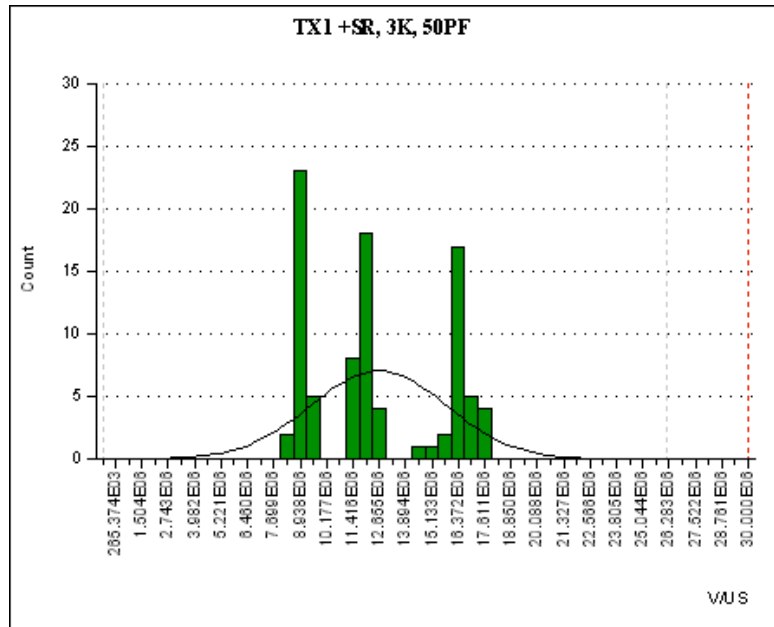
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=11.000, Test.Name=TX1 +SR, 3K, 50PF



Statistics: (V/US)

Max	17.647E06	25%	9.091E06	SpecHigh	30.000E06
Mean	12.499E06	10%	8.824E06	SpecLow	N/A
Min	8.451E06	N	90	PctWithinSpec	100.00
Range	9.196E06	Cp	N/A	PctDefSpec	0
StdDev	3.156E06	Cpl	N/A	NWithinSpec	90
W	0.8661	Cpu	1.8487	NOutsideSpec	0
WpValue	0.0000	Cpk	1.8487		
90%	16.905E06	Skew	0.2979		
75%	16.216E06	Kurtosis	-1.4024		
Median	12.000E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

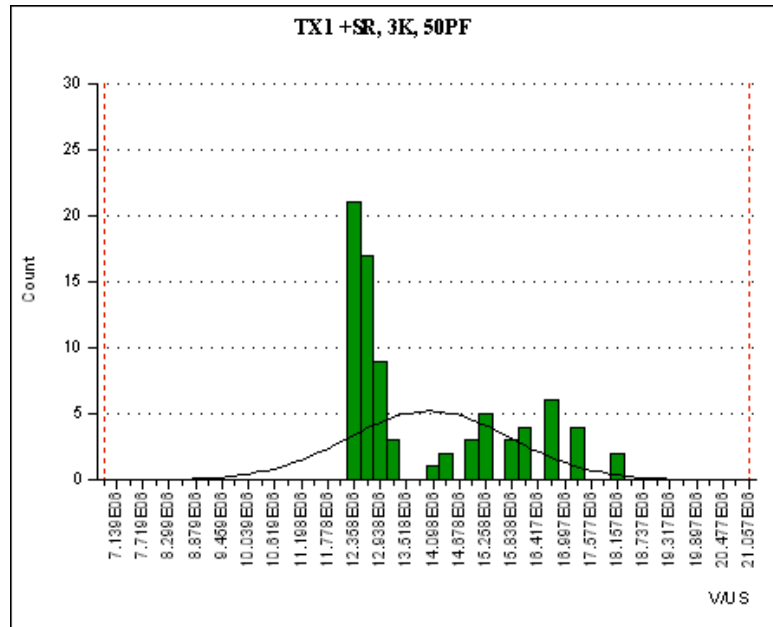
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
26.170E06	-354.097E03	100.00	0	90	0

Plot limits applied

NOutsidePlot
0

Test.Number=11.000, Test.Name=TX1 +SR, 3K, 50PF



Statistics: (V/US)

Max	18.182E06	25%	12.500E06	SpecHigh	21.057E06
Mean	13.953E06	10%	12.245E06	SpecLow	6.849E06
Min	12.245E06	N	80	PctWithinSpec	100.00
Range	5.937E06	Cp	1.3333	PctDefSpec	0
StdDev	1.776E06	Cpl	1.3333	NWithinSpec	80
W	0.8135	Cpu	1.3333	NOutsideSpec	0
WpValue	0.0000	Cpk	1.3333		
90%	16.667E06	Skew	0.8497		
75%	15.385E06	Kurtosis	-0.7649		
Median	13.043E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

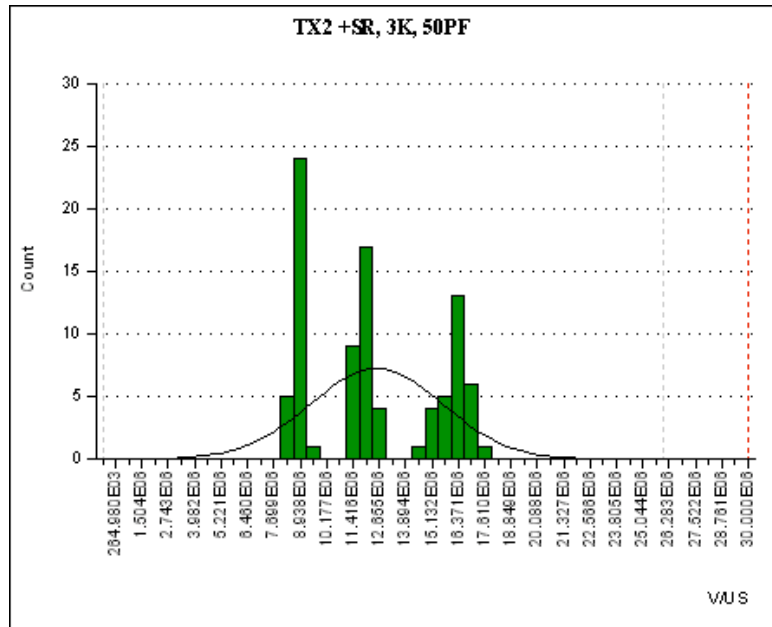
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=11.001, Test.Name=TX2 +SR, 3K, 50PF



Statistics: (V/US)

Max	17.647E06	25%	9.091E06	SpecHigh	30.000E06
Mean	12.373E06	10%	8.824E06	SpecLow	N/A
Min	8.451E06	N	90	PctWithinSpec	100.00
Range	9.196E06	Cp	N/A	c	
StdDev	3.076E06	Cpl	N/A	PctDefSpec	0
W	0.8721	Cpu	1.9103	NWithinSpec	90
WpValue	0.0000	Cpk	1.9103	NOutsideSpec	0
90%	16.667E06	Skew	0.2873		
75%	15.789E06	Kurtosis	-1.3883		
Median	12.000E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

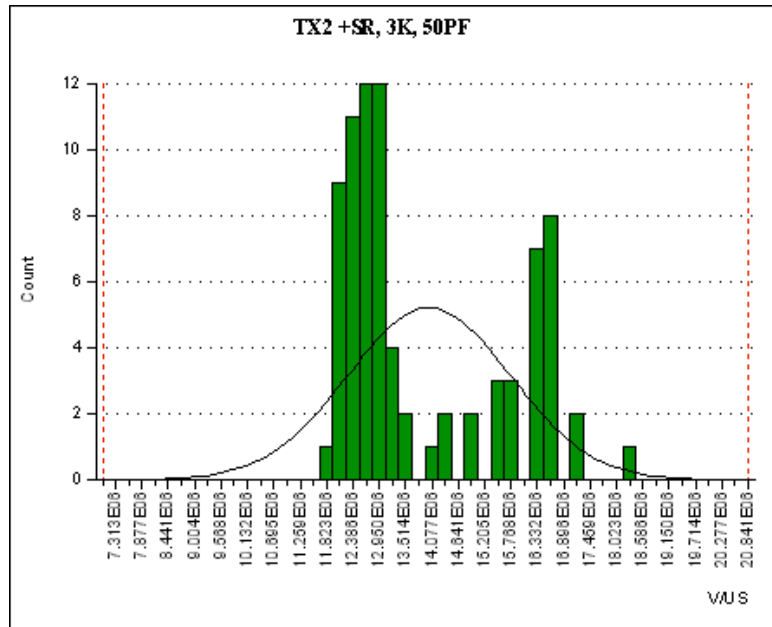
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
26.004E06	-354.500E03	100.00	0	90	0

Plot limits applied

NOutsidePlot
0

Test.Number=11.001, Test.Name=TX2 +SR, 3K, 50PF



Statistics: (V/US)

Max	18.182E06	25%	12.500E06	SpecHigh	20.841E06
Mean	13.936E06	10%	12.245E06	SpecLow	7.032E06
Min	11.765E06	N	80	PctWithinSpec	100.00
Range	6.417E06	Cp	1.3333	PctDefSpec	0
StdDev	1.726E06	Cpl	1.3333	NWithinSpec	80
W	0.8324	Cpu	1.3333	NOutsideSpec	0
WpValue	0.0000	Cpk	1.3333		
90%	16.667E06	Skew	0.7609		
75%	15.789E06	Kurtosis	-0.9631		
Median	13.043E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

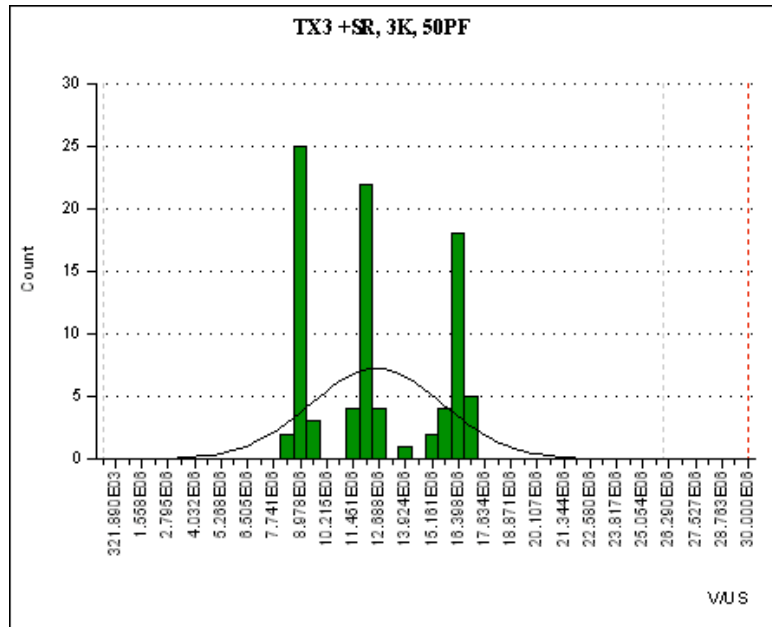
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=11.002, Test.Name=TX3 +SR, 3K, 50PF



Statistics: (V/US)

Max	17.143E06	25%	9.091E06	SpecHigh	30.000E06
Mean	12.437E06	10%	8.824E06	SpecLow	N/A
Min	8.333E06	N	90	PctWithinSpec	100.00
Range	8.810E06	Cp	N/A	c	
StdDev	3.078E06	Cpl	N/A	PctDefSpec	0
W	0.8616	Cpu	1.9019	NWithinSpec	90
WpValue	0.0000	Cpk	1.9019	NOutsideSpec	0
90%	16.667E06	Skew	0.2600		
75%	16.216E06	Kurtosis	-1.4246		
Median	12.000E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

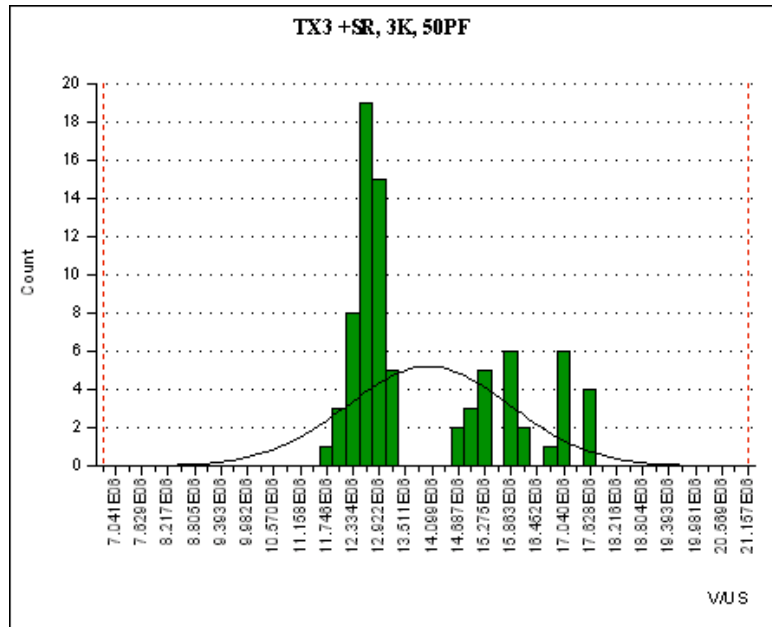
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
26.001E06	-296.404E03	100.00	0	90	0

Plot limits applied

NOutsidePlot
0

Test.Number=11.002, Test.Name=TX3 +SR, 3K, 50PF



Statistics: (V/US)

Max	17.647E06	25%	12.500E06	SpecHigh	21.157E06
Mean	13.952E06	10%	12.245E06	SpecLow	6.746E06
Min	11.765E06	N	80	PctWithinSpec	100.00
Range	5.882E06	Cp	1.3333	PctDefSpec	0
StdDev	1.801E06	Cpl	1.3333	NWithinSpec	80
W	0.8369	Cpu	1.3333	NOutsideSpec	0
WpValue	0.0000	Cpk	1.3333		
90%	17.143E06	Skew	0.8087		
75%	15.385E06	Kurtosis	-0.8106		
Median	13.043E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

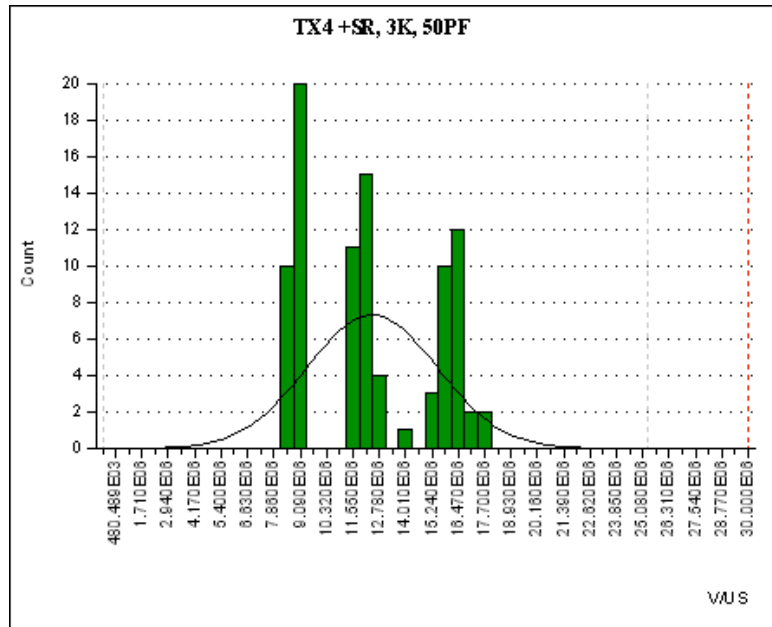
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=11.003, Test.Name=TX4 +SR, 3K, 50PF



Statistics: (V/US)

Max	17.647E06	25%	9.091E06	SpecHigh	30.000E06
Mean	12.311E06	10%	8.696E06	SpecLow	N/A
Min	8.451E06	N	90	PctWithinSpec	100.00
Range	9.196E06	Cp	N/A	PctDefSpec	0
StdDev	3.016E06	Cpl	N/A	NWithinSpec	90
W	0.8749	Cpu	1.9550	NOutsideSpec	0
WpValue	0.0000	Cpk	1.9550		
90%	16.216E06	Skew	0.2455		
75%	15.789E06	Kurtosis	-1.3832		
Median	12.000E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

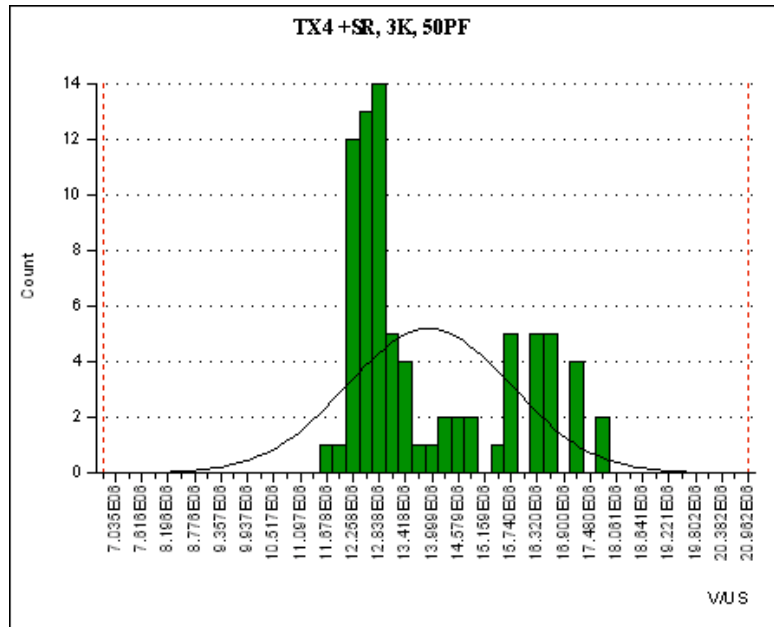
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
25.316E06	-134.501E03	100.00	0	90	0

Plot limits applied

NOutsidePlot
0

Test.Number=11.003, Test.Name=TX4 +SR, 3K, 50PF



Statistics: (V/US)

Max	17.647E06	25%	12.500E06	SpecHigh	20.962E06
Mean	13.854E06	10%	12.245E06	SpecLow	6.745E06
Min	11.538E06	N	80	PctWithinSpec	100.00
Range	6.109E06	Cp	1.3333	PctDefSpec	0
StdDev	1.777E06	Cpl	1.3333	NWithinSpec	80
W	0.8234	Cpu	1.3333	NOutsideSpec	0
WpValue	0.0000	Cpk	1.3333		
90%	16.667E06	Skew	0.8108		
75%	15.789E06	Kurtosis	-0.9021		
Median	12.766E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

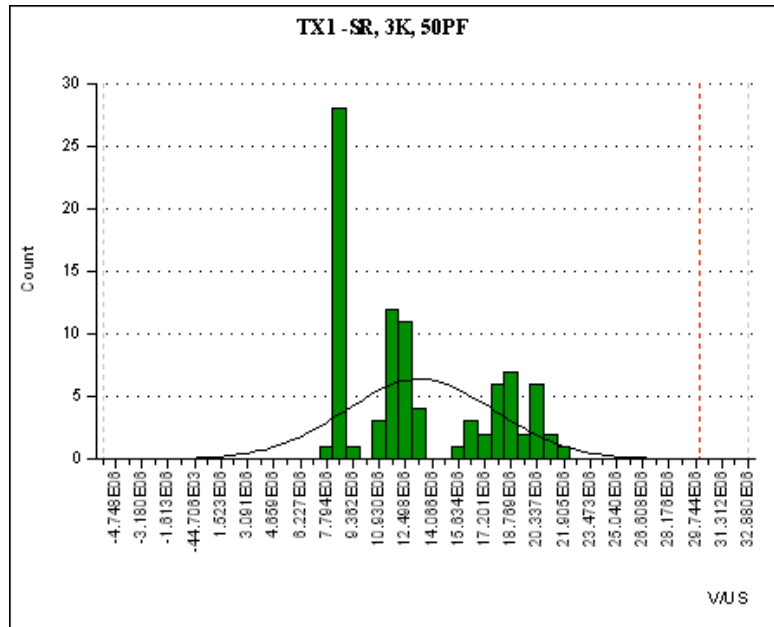
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=11.004, Test.Name=TX1 -SR, 3K, 50PF



Statistics: (V/US)

Max	22.222E06	25%	8.571E06	SpecHigh	30.000E06
Mean	13.171E06	10%	8.451E06	SpecLow	N/A
Min	8.108E06	N	90	PctWithinSpec	100.00
Range	14.114E06	Cp	N/A	c	
StdDev	4.416E06	Cpl	N/A	PctDefSpec	0
W	0.8725	Cpu	1.2704	NWithinSpec	90
WpValue	0.0000	Cpk	1.2704	NOutsideSpec	0
90%	19.677E06	Skew	0.4852		
75%	18.182E06	Kurtosis	-1.1815		
Median	12.122E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

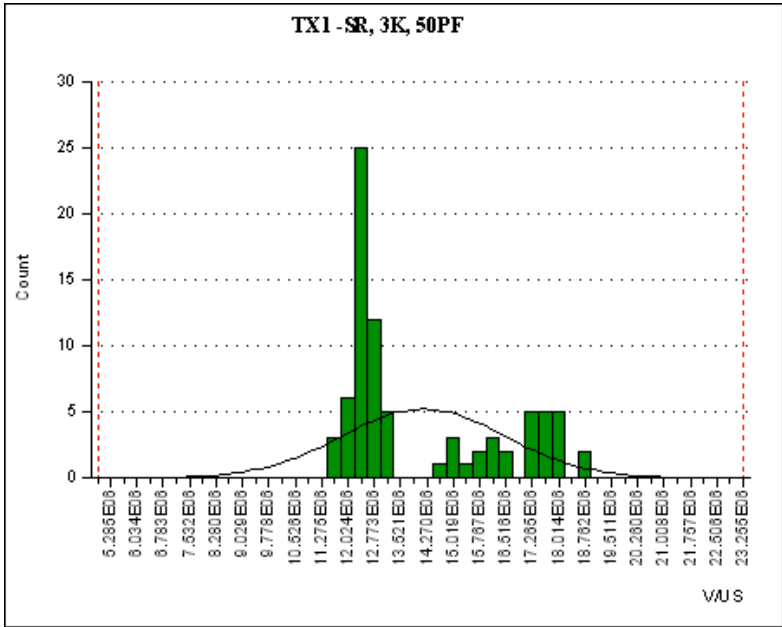
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
32.880E06	-5.532E06	100.00	0	90	0

Plot limits applied

NOutsidePlot
0

Test.Number=11.004, Test.Name=TX1 -SR, 3K, 50PF



Statistics: (V/US)

Max	18.750E06	25%	12.372E06	SpecHigh	23.255E06
Mean	14.083E06	10%	12.000E06	SpecLow	4.911E06
Min	11.765E06	N	80	PctWithinSpec	100.00
Range	6.985E06	Cp	1.3333	c	
StdDev	2.293E06	Cpl	1.3333	PctDefSpec	0
W	0.7908	Cpu	1.3333	NWithinSpec	80
WpValue	0.0000	Cpk	1.3333	NOutsideSpec	0
90%	17.647E06	Skew	0.8055		
75%	16.216E06	Kurtosis	-1.0258		
Median	12.766E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

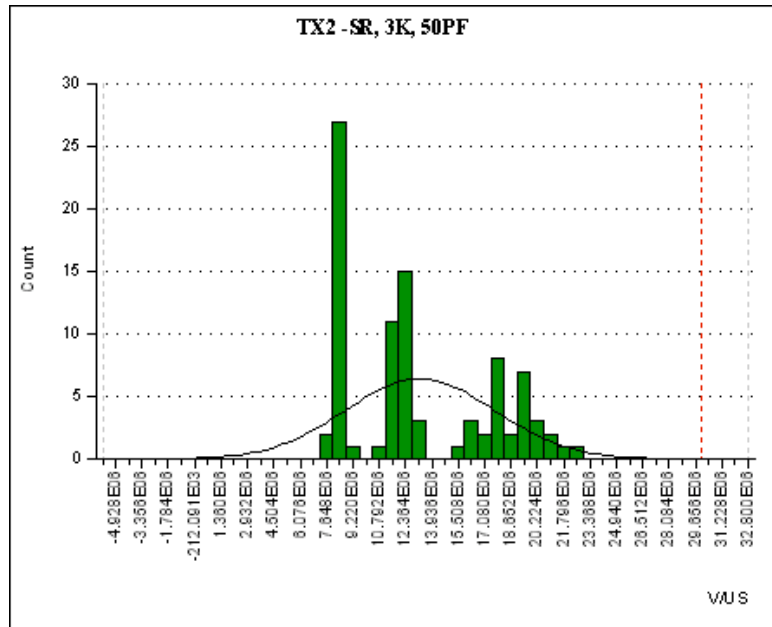
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=11.005, Test.Name=TX2 -SR, 3K, 50PF



Statistics: (V/US)

Max	22.222E06	25%	8.571E06	SpecHigh	30.000E06
Mean	13.036E06	10%	8.333E06	SpecLow	N/A
Min	7.895E06	N	90	PctWithinSpec	100.00
Range	14.327E06	Cp	N/A	c	
StdDev	4.400E06	Cpl	N/A	PctDefSpec	0
W	0.8689	Cpu	1.2850	NWithinSpec	90
WpValue	0.0000	Cpk	1.2850	NOutsideSpec	0
90%	19.355E06	Skew	0.4919		
75%	17.647E06	Kurtosis	-1.2028		
Median	12.000E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

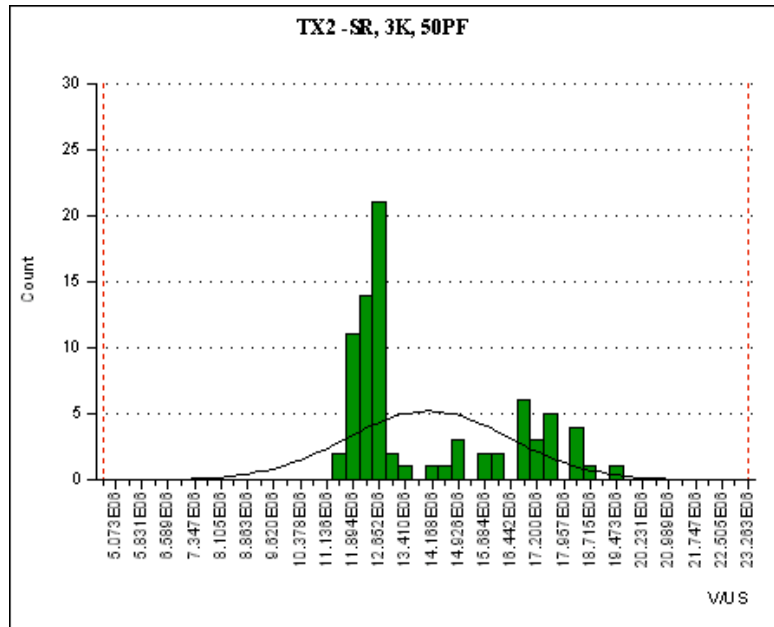
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
32.800E06	-5.714E06	100.00	0	90	0

Plot limits applied

NOutsidePlot
0

Test.Number=11.005, Test.Name=TX2 -SR, 3K, 50PF



Statistics: (V/US)

Max	19.355E06	25%	12.245E06	SpecHigh	23.263E06
Mean	13.978E06	10%	12.000E06	SpecLow	4.694E06
Min	11.538E06	N	80	PctWithinSpec	100.00
Range	7.816E06	Cp	1.3333	c	
StdDev	2.321E06	Cpl	1.3333	PctDefSpec	0
W	0.7990	Cpu	1.3333	NWithinSpec	80
WpValue	0.0000	Cpk	1.3333	NOutsideSpec	0
90%	17.647E06	Skew	0.8335		
75%	16.441E06	Kurtosis	-0.9196		
Median	12.633E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

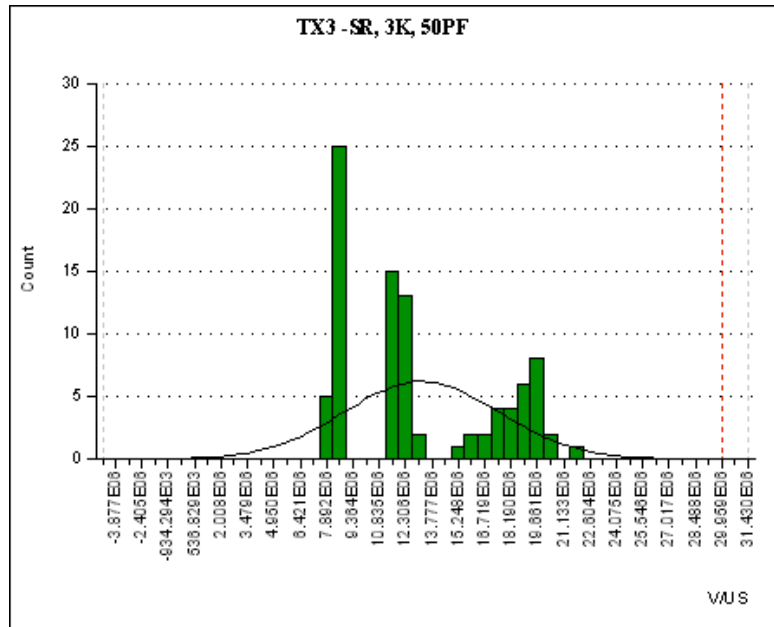
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=11.006, Test.Name=TX3 -SR, 3K, 50PF



Statistics: (V/US)

Max	22.222E06	25%	8.696E06	SpecHigh	30.000E06
Mean	13.028E06	10%	8.571E06	SpecLow	N/A
Min	7.792E06	N	90	PctWithinSpec	100.00
Range	14.430E06	Cp	N/A	c	
StdDev	4.257E06	Cpl	N/A	PctDefSpec	0
W	0.8711	Cpu	1.3290	NWithinSpec	90
WpValue	0.0000	Cpk	1.3290	NOutsideSpec	0
90%	19.355E06	Skew	0.4927		
75%	17.647E06	Kurtosis	-1.1928		
Median	11.882E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

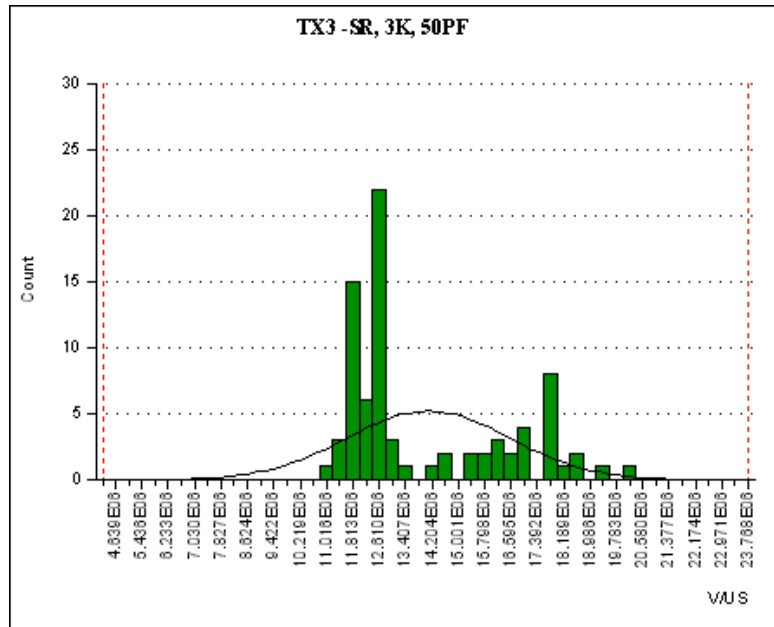
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
31.430E06	-4.612E06	100.00	0	90	0

Plot limits applied

NOutsidePlot
0

Test.Number=11.006, Test.Name=TX3 -SR, 3K, 50PF



Statistics: (V/US)

Max	20.000E06	25%	12.245E06	SpecHigh	23.768E06
Mean	14.004E06	10%	11.882E06	SpecLow	4.241E06
Min	11.111E06	N	80	PctWithinSpec	100.00
Range	8.889E06	Cp	1.3333	PctDefSpec	0
StdDev	2.441E06	Cpl	1.3333	NWithinSpec	80
W	0.8241	Cpu	1.3333	NOutsideSpec	0
WpValue	0.0000	Cpk	1.3333		
90%	17.647E06	Skew	0.8435		
75%	16.216E06	Kurtosis	-0.7839		
Median	12.766E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

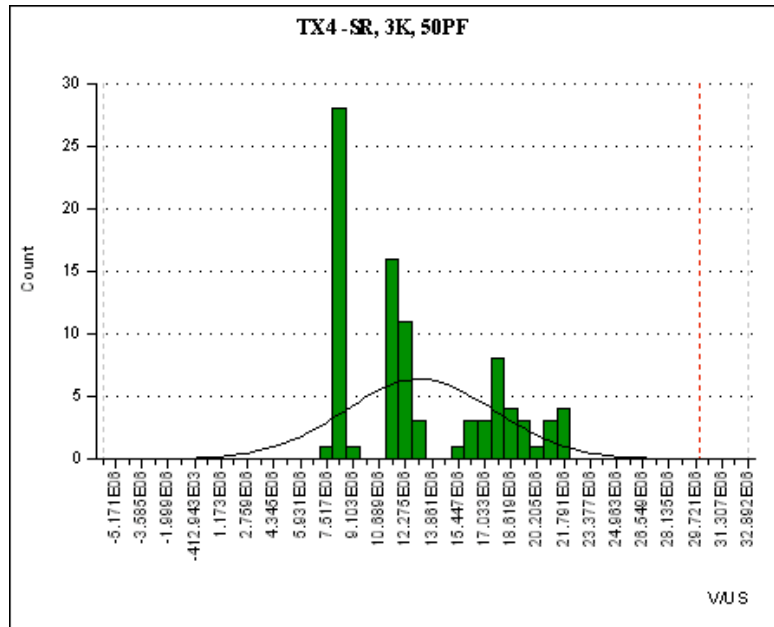
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=11.007, Test.Name=TX4 -SR, 3K, 50PF



Statistics: (V/US)

Max	21.429E06	25%	8.333E06	SpecHigh	30.000E06
Mean	12.935E06	10%	8.108E06	SpecLow	N/A
Min	7.895E06	N	90	PctWithinSpec	100.00
Range	13.534E06	Cp	N/A	PctDefSpec	0
StdDev	4.461E06	Cpl	N/A	NWithinSpec	90
W	0.8696	Cpu	1.2752	NOutsideSpec	0
WpValue	0.0000	Cpk	1.2752		
90%	19.355E06	Skew	0.5198		
75%	17.647E06	Kurtosis	-1.1354		
Median	11.652E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

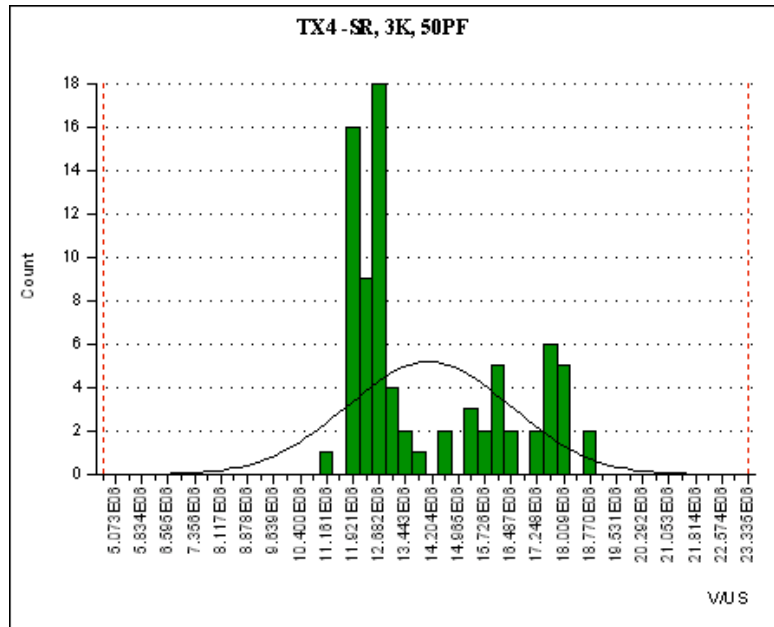
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
32.892E06	-5.964E06	100.00	0	90	0

Plot limits applied

NOutsidePlot
0

Test.Number=11.007, Test.Name=TX4 -SR, 3K, 50PF



Statistics: (V/US)

Max	18.750E06	25%	12.245E06	SpecHigh	23.335E06
Mean	14.014E06	10%	12.000E06	SpecLow	4.693E06
Min	11.321E06	N	80	PctWithinSpec	100.00
Range	7.429E06	Cp	1.3333	PctDefSpec	0
StdDev	2.330E06	Cpl	1.3333	NWithinSpec	80
W	0.8085	Cpu	1.3333	NOutsideSpec	0
WpValue	0.0000	Cpk	1.3333		
90%	17.647E06	Skew	0.7797		
75%	16.216E06	Kurtosis	-1.0208		
Median	12.633E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

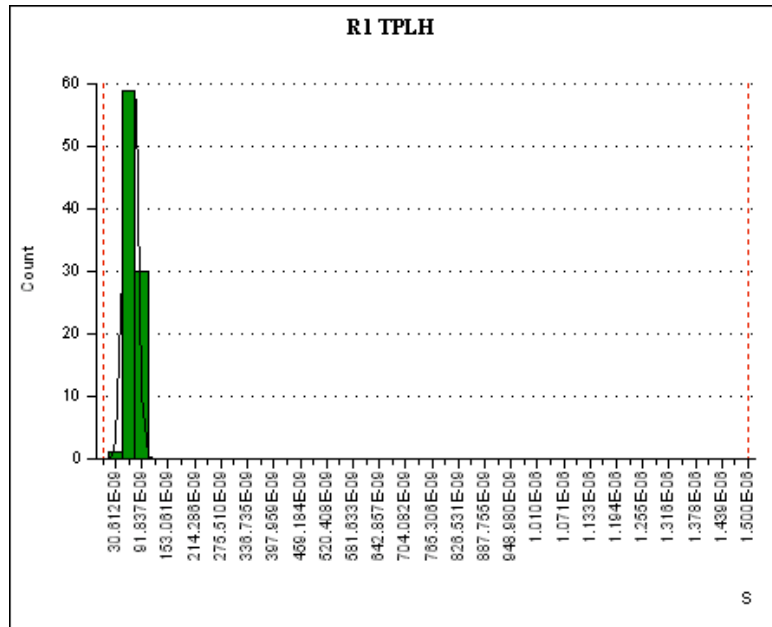
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.000, Test.Name=R1 TPLH



Statistics: (S)

Max	79.645E-09	25%	47.114E-09	SpecHigh	1.500E-06
Mean	63.565E-09	10%	46.649E-09	SpecLow	0
Min	45.905E-09	N	90	PctWithinSpec	100.00
Range	33.739E-09	Cp	>4.0000	PctDefSpec	0
StdDev	12.849E-09	Cpl	1.6491	NWithinSpec	90
W	0.8161	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	1.6491		
90%	78.297E-09	Skew	-0.2440		
75%	77.600E-09	Kurtosis	-1.5023		
Median	65.531E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

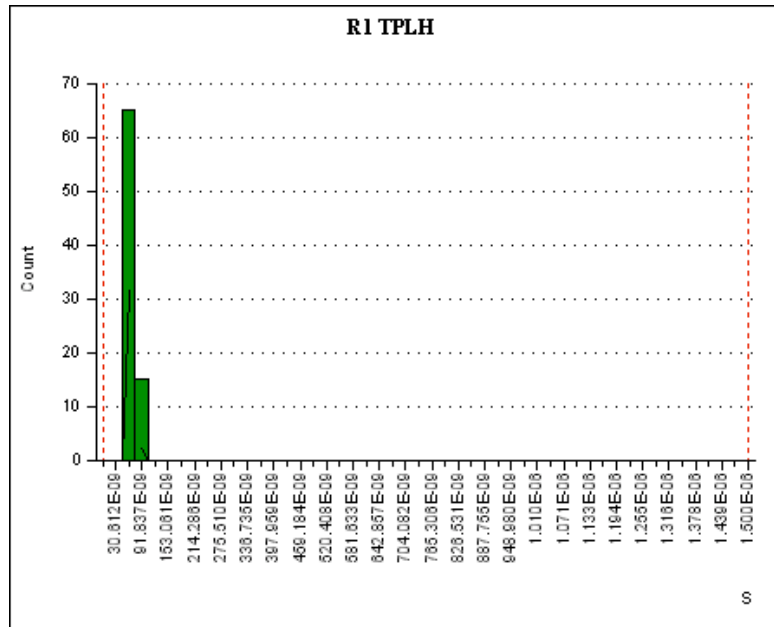
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=12.000, Test.Name=R1 TPLH



Statistics: (S)

Max	77.460E-09	25%	63.726E-09	SpecHigh	1.500E-06
Mean	71.390E-09	10%	61.414E-09	SpecLow	0
Min	60.281E-09	N	80	PctWithinSpec	100.00
Range	17.179E-09	Cp	>4.0000	c	
StdDev	6.428E-09	Cpl	3.7021	PctDefSpec	0
W	0.7453	Cpu	>4.0000	NWithinSpec	80
WpValue	0.0000	Cpk	3.7021	NOutsideSpec	0
90%	76.752E-09	Skew	-0.6873		
75%	76.327E-09	Kurtosis	-1.3809		
Median	75.619E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

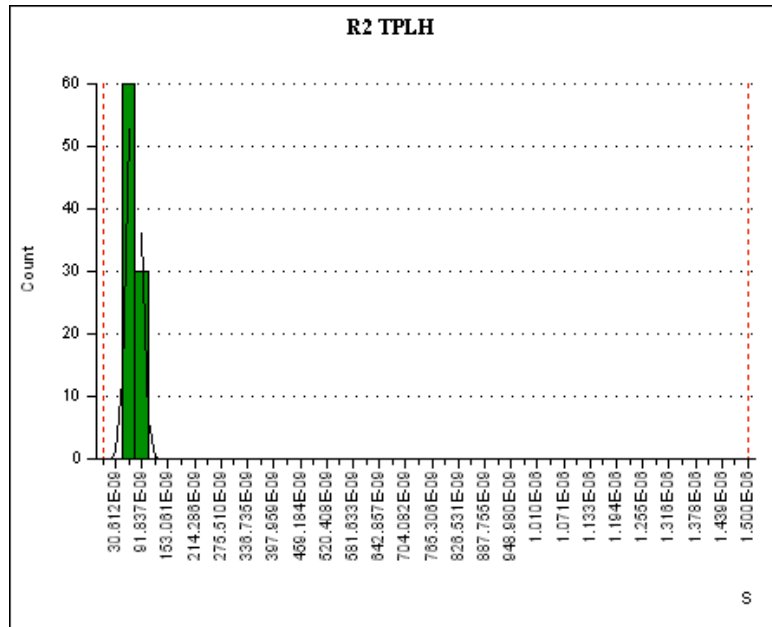
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.001, Test.Name=R2 TPLH



Statistics: (S)

Max	90.984E-09	25%	54.178E-09	SpecHigh	1.500E-06
Mean	72.336E-09	10%	53.202E-09	SpecLow	0
Min	52.319E-09	N	90	PctWithinSpec	100.00
Range	38.665E-09	Cp	>4.0000	PctDefSpec	0
StdDev	14.524E-09	Cpl	1.6601	NWithinSpec	90
W	0.8256	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	1.6601		
90%	89.450E-09	Skew	-0.2022		
75%	88.381E-09	Kurtosis	-1.4990		
Median	74.178E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

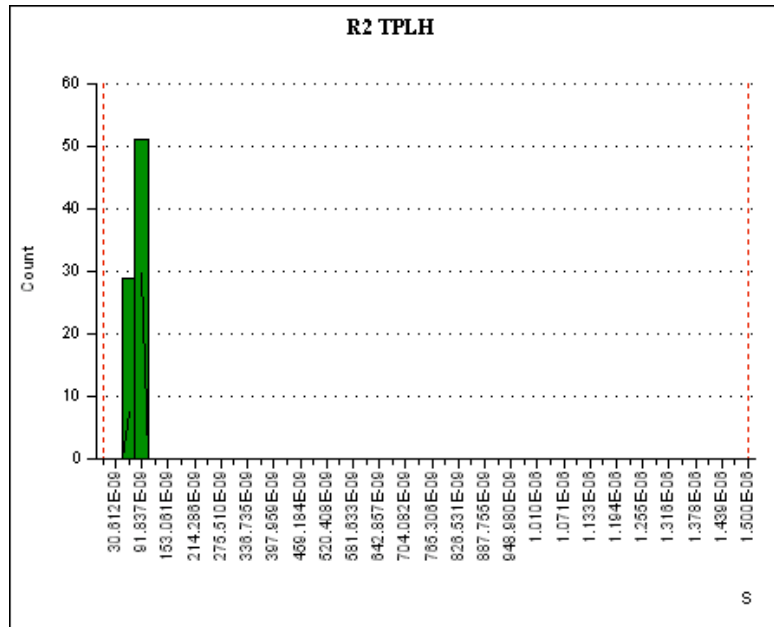
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=12.001, Test.Name=R2 TPLH



Statistics: (S)

Max	84.634E-09	25%	68.587E-09	SpecHigh	1.500E-06
Mean	77.387E-09	10%	66.180E-09	SpecLow	0
Min	65.284E-09	N	80	PctWithinSpec	100.00
Range	19.350E-09	Cp	>4.0000	c	
StdDev	7.253E-09	Cpl	3.5566	PctDefSpec	0
W	0.7402	Cpu	>4.0000	NWithinSpec	80
WpValue	0.0000	Cpk	3.5566	NOutsideSpec	0
90%	83.407E-09	Skew	-0.6673		
75%	82.840E-09	Kurtosis	-1.4260		
Median	82.274E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

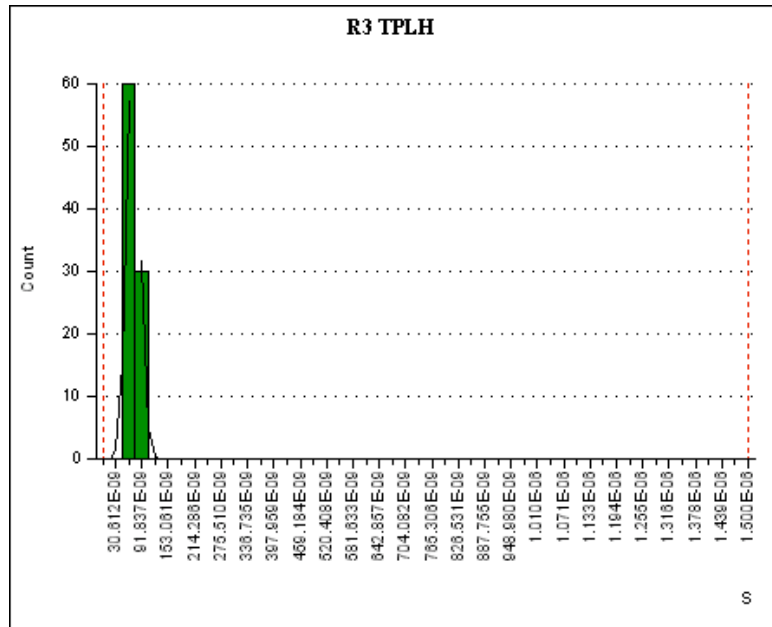
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.002, Test.Name=R3 TPLH



Statistics: (S)

Max	89.404E-09	25%	52.783E-09	SpecHigh	1.500E-06
Mean	70.905E-09	10%	51.947E-09	SpecLow	0
Min	51.110E-09	N	90	PctWithinSpec	100.00
Range	38.293E-09	Cp	>4.0000	PctDefSpec	0
StdDev	14.406E-09	Cpl	1.6407	NWithinSpec	90
W	0.8231	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	1.6407		
90%	87.638E-09	Skew	-0.1972		
75%	86.987E-09	Kurtosis	-1.5004		
Median	72.644E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

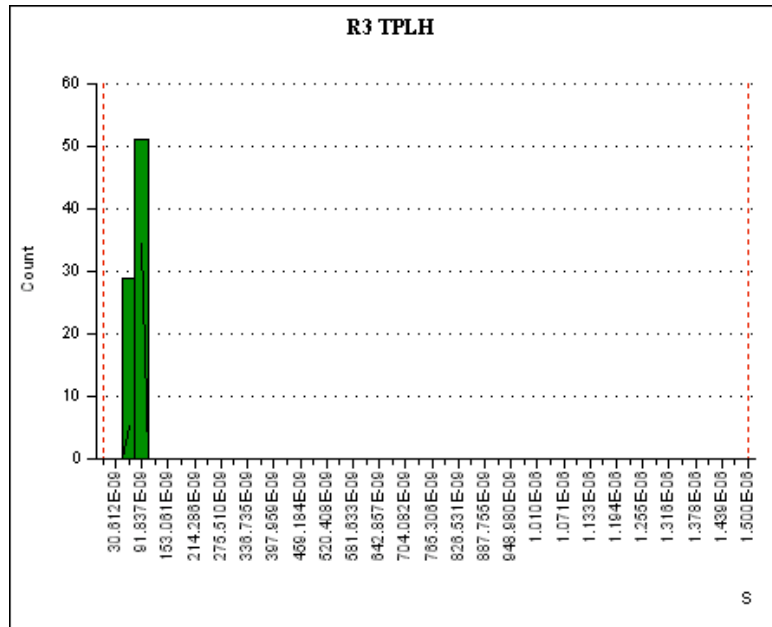
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=12.002, Test.Name=R3 TPLH



Statistics: (S)

Max	85.200E-09	25%	69.720E-09	SpecHigh	1.500E-06
Mean	78.155E-09	10%	67.077E-09	SpecLow	0
Min	66.133E-09	N	80	PctWithinSpec	100.00
Range	19.067E-09	Cp	>4.0000	PctDefSpec	0
StdDev	7.121E-09	Cpl	3.6584	NWithinSpec	80
W	0.7544	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	3.6584		
90%	84.492E-09	Skew	-0.6678		
75%	83.454E-09	Kurtosis	-1.4008		
Median	82.557E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

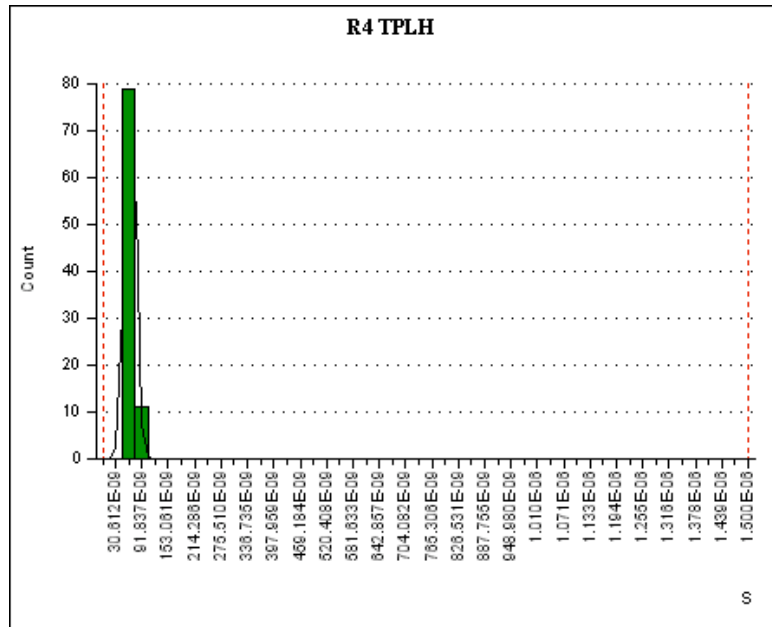
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.003, Test.Name=R4 TPLH



Statistics: (S)

Max	78.901E-09	25%	47.114E-09	SpecHigh	1.500E-06
Mean	62.801E-09	10%	46.556E-09	SpecLow	0
Min	46.091E-09	N	90	PctWithinSpec	100.00
Range	32.810E-09	Cp	>4.0000	PctDefSpec	0
StdDev	12.222E-09	Cpl	1.7128	NWithinSpec	90
W	0.8208	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	1.7128		
90%	76.717E-09	Skew	-0.2529		
75%	76.113E-09	Kurtosis	-1.4975		
Median	64.695E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

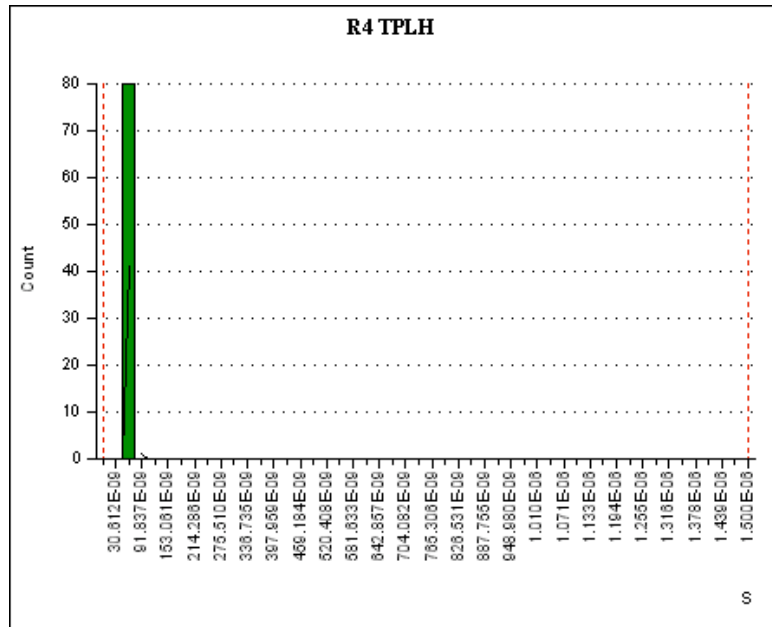
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=12.003, Test.Name=R4 TPLH



Statistics: (S)

Max	76.327E-09	25%	62.452E-09	SpecHigh	1.500E-06
Mean	70.273E-09	10%	60.847E-09	SpecLow	0
Min	59.715E-09	N	80	PctWithinSpec	100.00
Range	16.613E-09	Cp	>4.0000	c	
StdDev	6.313E-09	Cpl	3.7105	PctDefSpec	0
W	0.7334	Cpu	>4.0000	NWithinSpec	80
WpValue	0.0000	Cpk	3.7105	NOutsideSpec	0
90%	75.525E-09	Skew	-0.6785		
75%	75.100E-09	Kurtosis	-1.4133		
Median	74.534E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

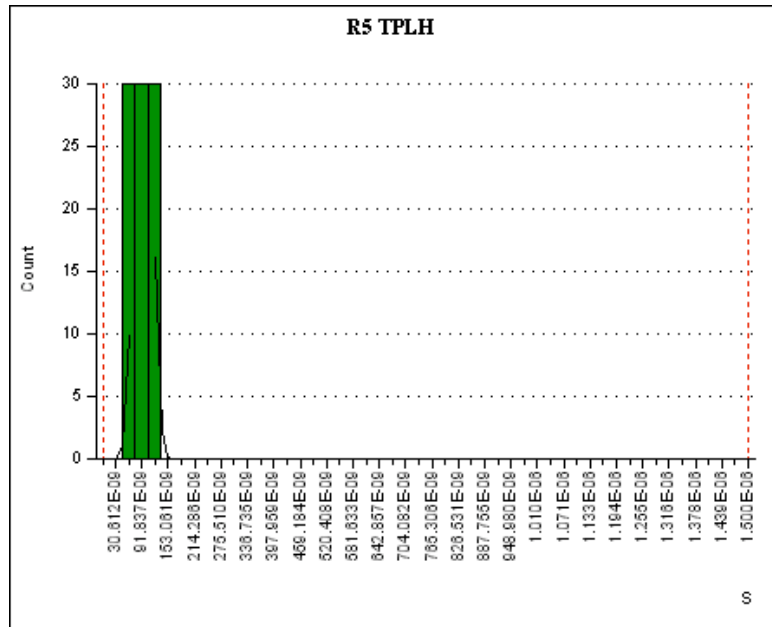
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.004, Test.Name=R5 TPLH



Statistics: (S)

Max	113.848E-09	25%	72.116E-09	SpecHigh	1.500E-06
Mean	92.239E-09	10%	71.279E-09	SpecLow	0
Min	69.235E-09	N	90	PctWithinSpec	100.00
Range	44.614E-09	Cp	>4.0000	PctDefSpec	0
StdDev	16.451E-09	Cpl	1.8690	NWithinSpec	90
W	0.8308	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	1.8690		
90%	111.896E-09	Skew	-0.1019		
75%	110.967E-09	Kurtosis	-1.5010		
Median	93.285E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

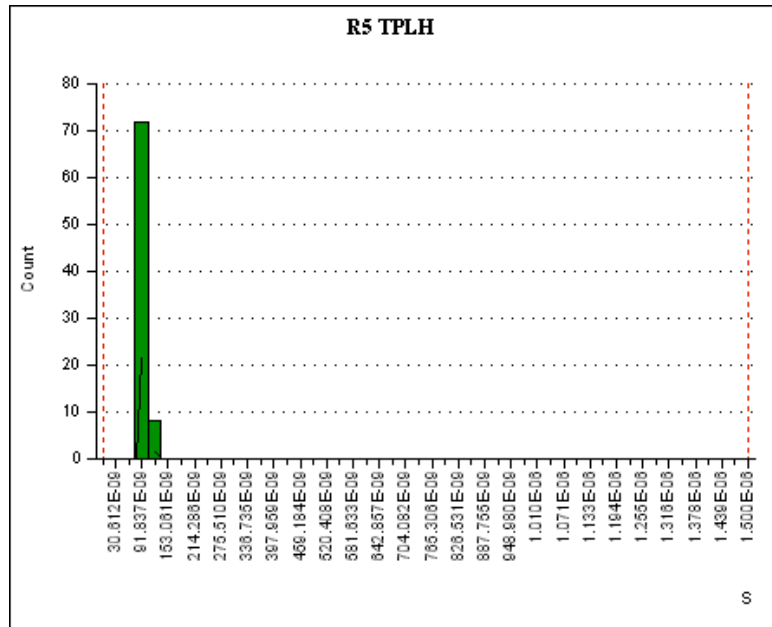
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=12.004, Test.Name=R5 TPLH



Statistics: (S)

Max	113.328E-09	25%	101.907E-09	SpecHigh	1.500E-06
Mean	101.842E-09	10%	90.155E-09	SpecLow	0
Min	81.424E-09	N	80	PctWithinSpec	100.00
Range	31.904E-09	Cp	>4.0000	PctDefSpec	0
StdDev	5.857E-09	Cpl	>4.0000	NWithinSpec	80
W	0.7893	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	107.146E-09	Skew	-1.6697		
75%	104.833E-09	Kurtosis	2.8104		
Median	102.757E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

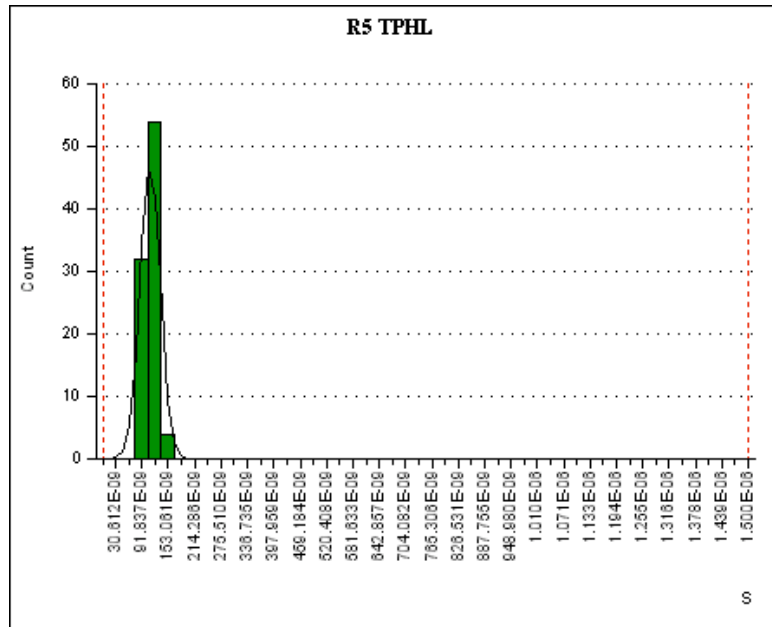
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.005, Test.Name=R5 TPHL



Statistics: (S)

Max	138.851E-09	25%	80.853E-09	SpecHigh	1.500E-06
Mean	108.363E-09	10%	79.598E-09	SpecLow	0
Min	77.600E-09	N	90	PctWithinSpec	100.00
Range	61.251E-09	Cp	>4.0000	PctDefSpec	0
StdDev	23.302E-09	Cpl	1.5501	NWithinSpec	90
W	0.8216	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	1.5501		
90%	137.549E-09	Skew	0.0371		
75%	136.620E-09	Kurtosis	-1.5062		
Median	107.836E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

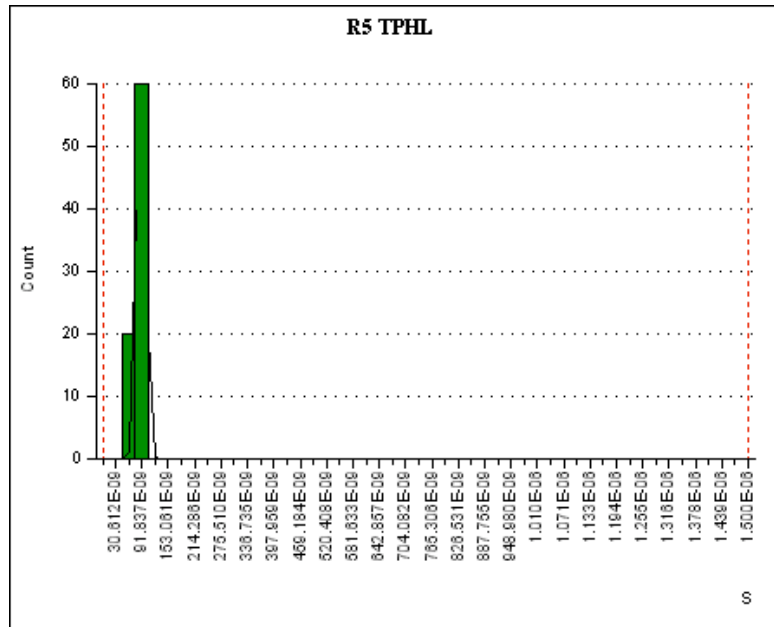
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=12.005, Test.Name=R5 TPHL



Statistics: (S)

Max	96.621E-09	25%	76.846E-09	SpecHigh	1.500E-06
Mean	87.970E-09	10%	73.732E-09	SpecLow	0
Min	71.985E-09	N	80	PctWithinSpec	100.00
Range	24.636E-09	Cp	>4.0000	PctDefSpec	0
StdDev	9.280E-09	Cpl	3.1599	NWithinSpec	80
W	0.7225	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	3.1599		
90%	95.536E-09	Skew	-0.6820		
75%	95.158E-09	Kurtosis	-1.4229		
Median	94.214E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

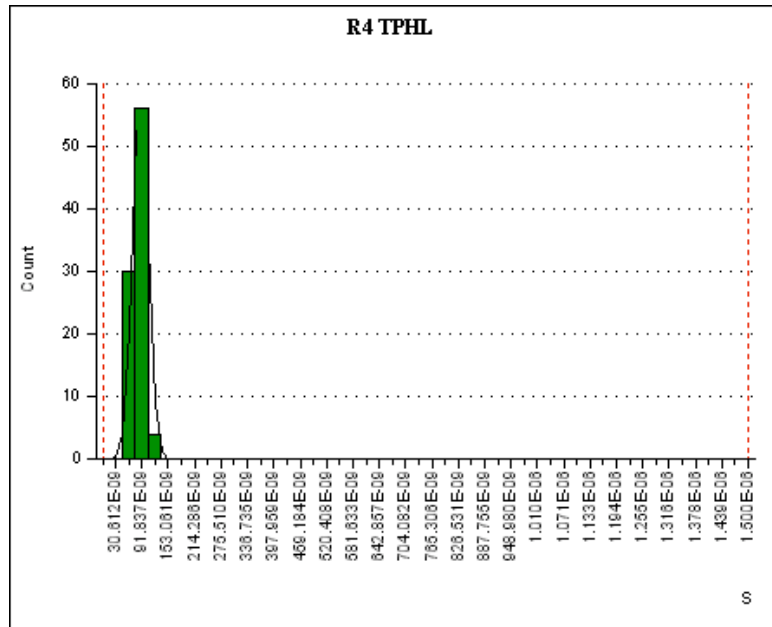
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.006, Test.Name=R4 TPHL



Statistics: (S)

Max	107.342E-09	25%	64.959E-09	SpecHigh	1.500E-06
Mean	85.832E-09	10%	64.030E-09	SpecLow	0
Min	62.914E-09	N	90	PctWithinSpec	100.00
Range	44.428E-09	Cp	>4.0000	PctDefSpec	0
StdDev	17.197E-09	Cpl	1.6637	NWithinSpec	90
W	0.8212	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	1.6637		
90%	106.831E-09	Skew	-0.0658		
75%	106.041E-09	Kurtosis	-1.5069		
Median	86.498E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

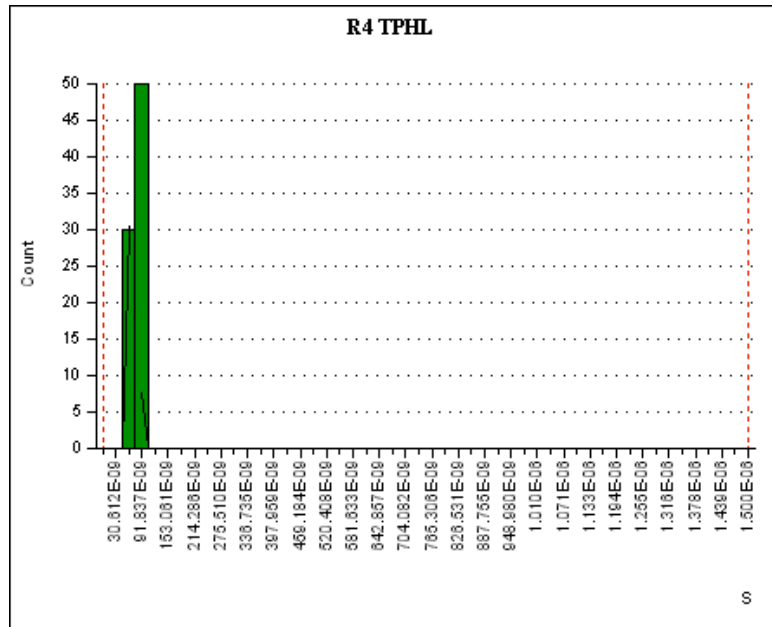
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=12.006, Test.Name=R4 TPHL



Statistics: (S)

Max	79.159E-09	25%	63.632E-09	SpecHigh	1.500E-06
Mean	72.562E-09	10%	61.461E-09	SpecLow	0
Min	60.092E-09	N	80	PctWithinSpec	100.00
Range	19.067E-09	Cp	>4.0000	c	
StdDev	7.292E-09	Cpl	3.3170	PctDefSpec	0
W	0.7253	Cpu	>4.0000	NWithinSpec	80
WpValue	0.0000	Cpk	3.3170	NOutsideSpec	0
90%	78.498E-09	Skew	-0.6851		
75%	78.121E-09	Kurtosis	-1.4135		
Median	77.413E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

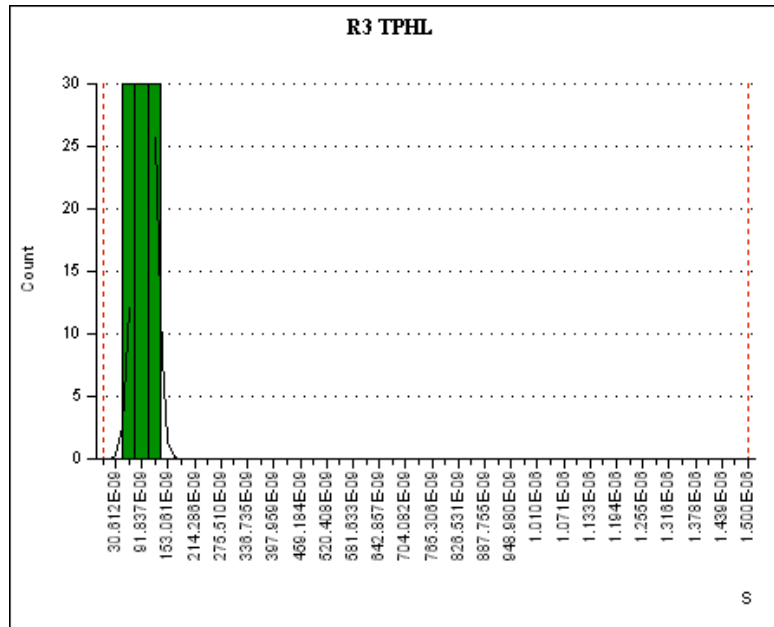
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.007, Test.Name=R3 TPHL



Statistics: (S)

Max	121.563E-09	25%	70.815E-09	SpecHigh	1.500E-06
Mean	95.187E-09	10%	69.421E-09	SpecLow	0
Min	68.677E-09	N	90	PctWithinSpec	100.00
Range	52.886E-09	Cp	>4.0000	PctDefSpec	0
StdDev	20.382E-09	Cpl	1.5567	NWithinSpec	90
W	0.8212	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	1.5567		
90%	120.262E-09	Skew	-0.0123		
75%	119.425E-09	Kurtosis	-1.5068		
Median	95.377E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

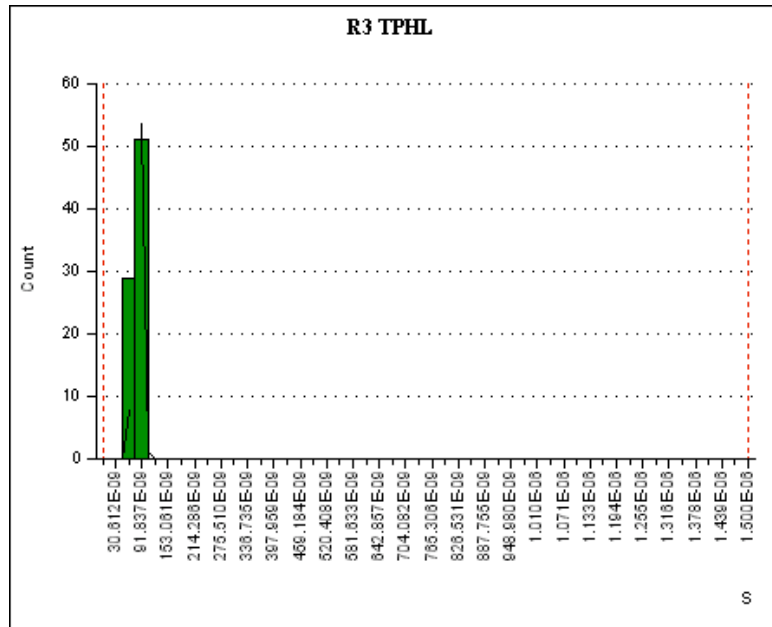
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=12.007, Test.Name=R3 TPHL



Statistics: (S)

Max	88.032E-09	25%	69.342E-09	SpecHigh	1.500E-06
Mean	79.541E-09	10%	66.888E-09	SpecLow	0
Min	65.284E-09	N	80	PctWithinSpec	100.00
Range	22.748E-09	Cp	>4.0000	PctDefSpec	0
StdDev	8.435E-09	Cpl	3.1434	NWithinSpec	80
W	0.7303	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	3.1434		
90%	86.333E-09	Skew	-0.6699		
75%	85.861E-09	Kurtosis	-1.4321		
Median	85.247E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

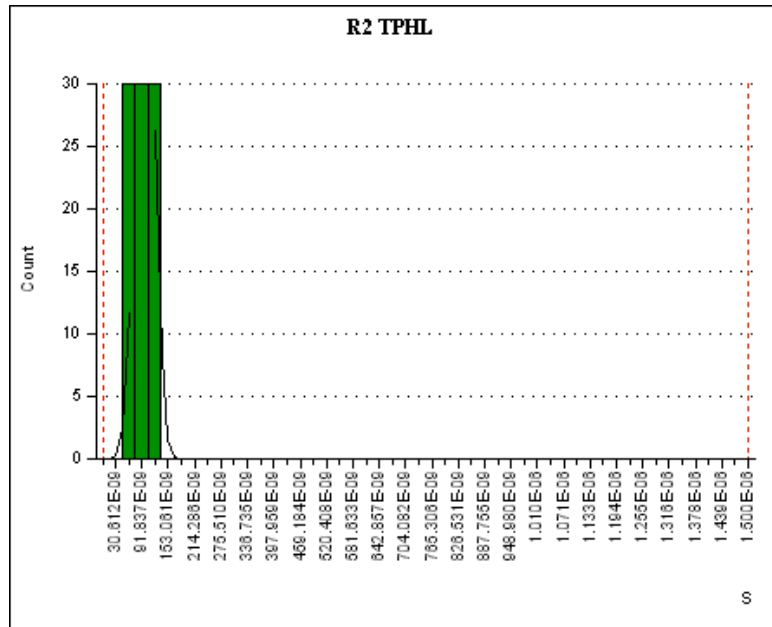
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.008, Test.Name=R2 TPHL



Statistics: (S)

Max	121.842E-09	25%	71.279E-09	SpecHigh	1.500E-06
Mean	95.569E-09	10%	70.164E-09	SpecLow	0
Min	69.142E-09	N	90	PctWithinSpec	100.00
Range	52.700E-09	Cp	>4.0000	PctDefSpec	0
StdDev	20.270E-09	Cpl	1.5716	NWithinSpec	90
W	0.8202	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	1.5716		
90%	120.447E-09	Skew	-0.0115		
75%	119.797E-09	Kurtosis	-1.5070		
Median	95.563E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

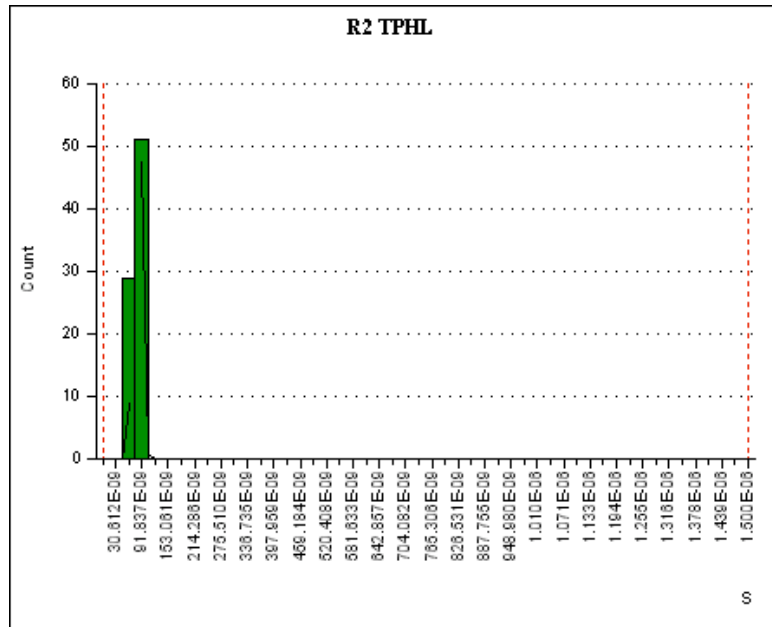
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=12.008, Test.Name=R2 TPHL



Statistics: (S)

Max	86.238E-09	25%	68.587E-09	SpecHigh	1.500E-06
Mean	78.823E-09	10%	66.133E-09	SpecLow	0
Min	65.378E-09	N	80	PctWithinSpec	100.00
Range	20.860E-09	Cp	>4.0000	c	
StdDev	8.292E-09	Cpl	3.1685	PctDefSpec	0
W	0.7186	Cpu	>4.0000	NWithinSpec	80
WpValue	0.0000	Cpk	3.1685	NOutsideSpec	0
90%	85.672E-09	Skew	-0.6784		
75%	85.106E-09	Kurtosis	-1.4328		
Median	84.539E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

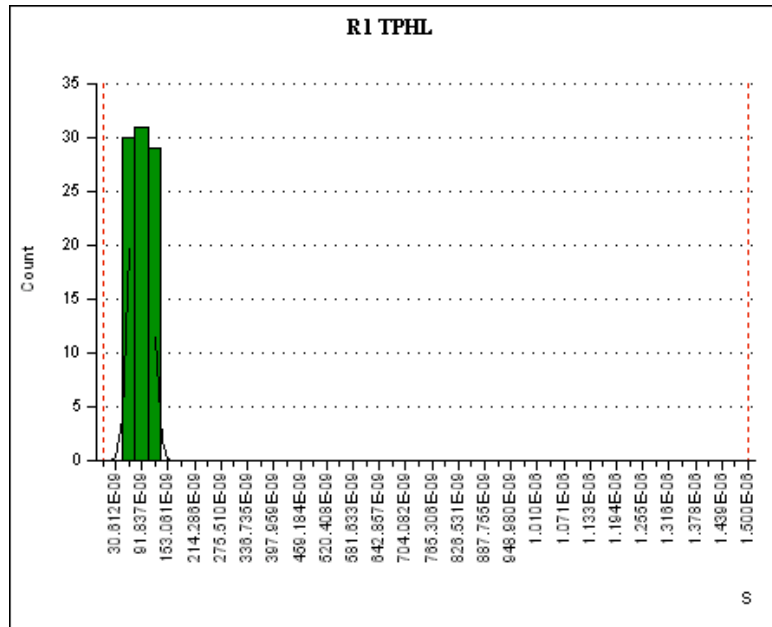
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.009, Test.Name=R1 TPHL



Statistics: (S)

Max	110.038E-09	25%	65.145E-09	SpecHigh	1.500E-06
Mean	87.071E-09	10%	64.355E-09	SpecLow	0
Min	63.658E-09	N	90	PctWithinSpec	100.00
Range	46.380E-09	Cp	>4.0000	PctDefSpec	0
StdDev	17.944E-09	Cpl	1.6174	NWithinSpec	90
W	0.8190	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	1.6174		
90%	108.922E-09	Skew	-0.0509		
75%	108.272E-09	Kurtosis	-1.5065		
Median	87.660E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

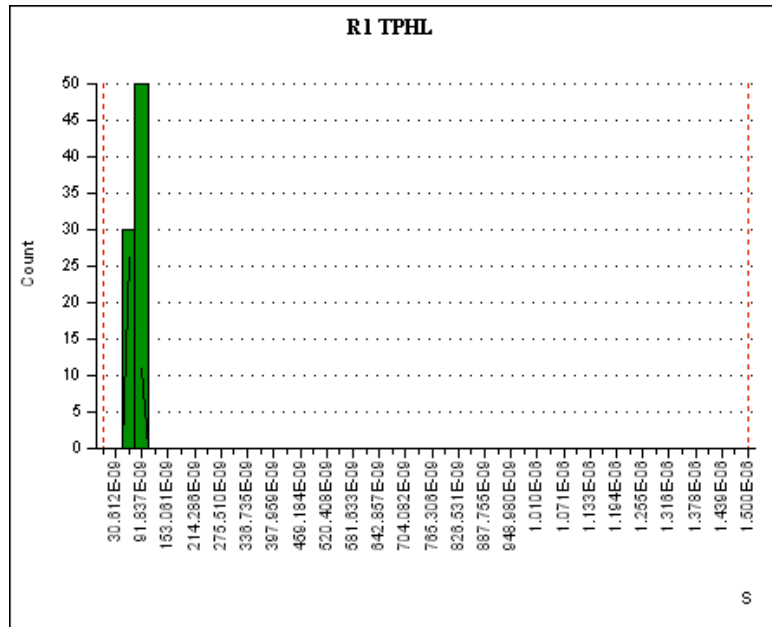
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=12.009, Test.Name=R1 TPHL



Statistics: (S)

Max	80.009E-09	25%	64.104E-09	SpecHigh	1.500E-06
Mean	73.361E-09	10%	61.791E-09	SpecLow	0
Min	60.753E-09	N	80	PctWithinSpec	100.00
Range	19.256E-09	Cp	>4.0000	c	
StdDev	7.454E-09	Cpl	3.2808	PctDefSpec	0
W	0.7252	Cpu	>4.0000	NWithinSpec	80
WpValue	0.0000	Cpk	3.2808	NOutsideSpec	0
90%	79.537E-09	Skew	-0.6788		
75%	78.970E-09	Kurtosis	-1.4253		
Median	78.404E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

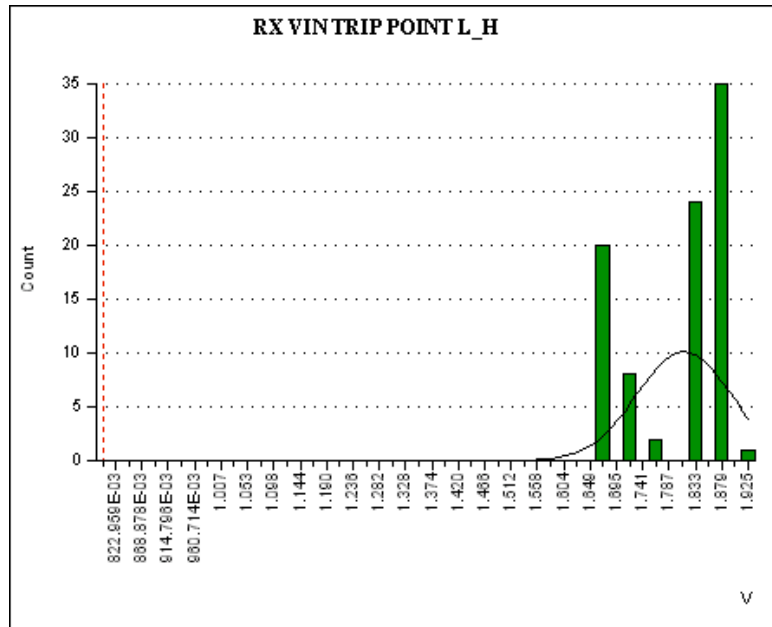
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.000, Test.Name=RX VIN TRIP POINT L_H



Statistics: (V)

Max	1.925	25%	1.725	SpecHigh	N/A
Mean	1.802	10%	1.675	SpecLow	800.000E-03
Min	1.675	N	90	PctWithinSpec	100.00
Range	250.000E-03	Cp	N/A	PctDefSpec	0
StdDev	81.130E-03	Cpl	>4.0000	NWithinSpec	90
W	0.7862	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	1.875	Skew	-0.6301		
75%	1.875	Kurtosis	-1.2337		
Median	1.825				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

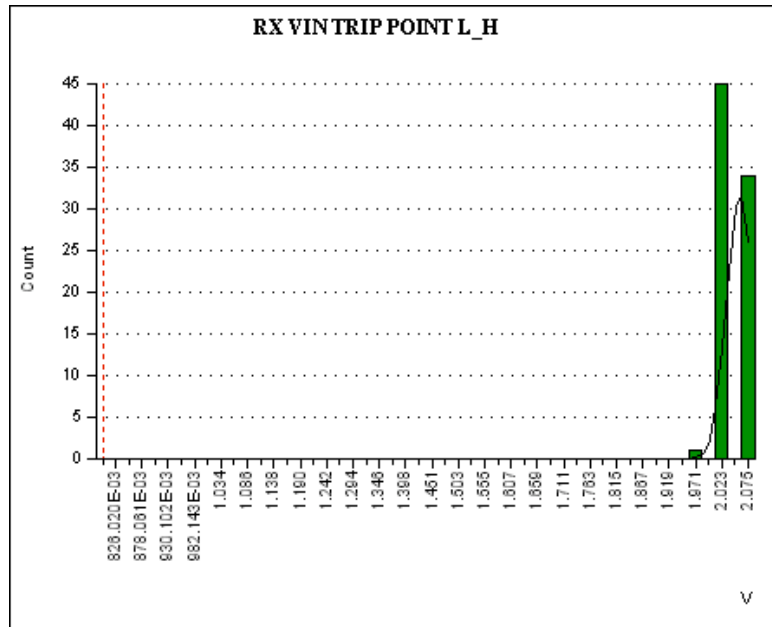
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=13.000, Test.Name=RX VIN TRIP POINT L_H



Statistics: (V)

Max	2.075	25%	2.025	SpecHigh	N/A
Mean	2.046	10%	2.025	SpecLow	800.000E-03
Min	1.975	N	80	PctWithinSpec	100.00
Range	100.000E-03	Cp	N/A	c	
StdDev	26.016E-03	Cpl	>4.0000	PctDefSpec	0
W	0.6755	Cpu	N/A	NWithinSpec	80
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	2.075	Skew	0.0846		
75%	2.075	Kurtosis	-1.3781		
Median	2.025				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

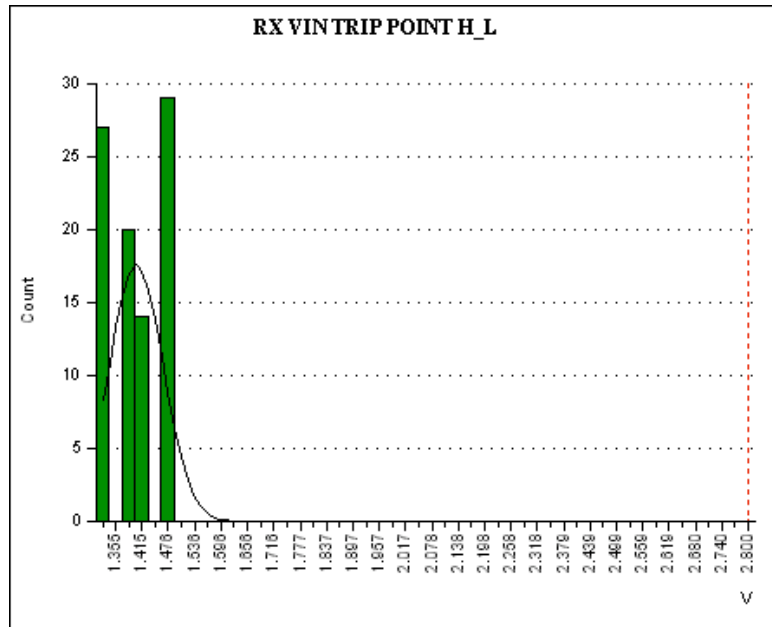
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.001, Test.Name=RX VIN TRIP POINT H_L



Statistics: (V)

Max	1.475	25%	1.325	SpecHigh	2.800
Mean	1.400	10%	1.325	SpecLow	N/A
Min	1.325	N	90	PctWithinSpec	100.00
Range	150.000E-03	Cp	N/A	PctDefSpec	0
StdDev	61.466E-03	Cpl	N/A	NWithinSpec	90
W	0.8162	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	1.475	Skew	0.0371		
75%	1.475	Kurtosis	-1.6006		
Median	1.375				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

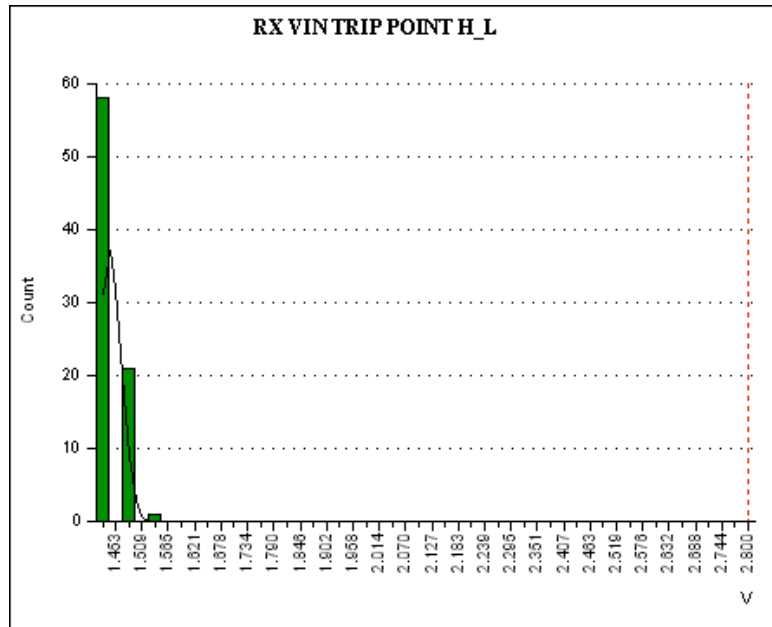
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=13.001, Test.Name=RX VIN TRIP POINT H_L



Statistics: (V)

Max	1.525	25%	1.425	SpecHigh	2.800
Mean	1.439	10%	1.425	SpecLow	N/A
Min	1.425	N	80	PctWithinSpec	100.00
Range	100.000E-03	Cp	N/A	PctDefSpec	0
StdDev	24.122E-03	Cpl	N/A	NWithinSpec	80
W	0.5852	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	1.475	Skew	1.2995		
75%	1.475	Kurtosis	0.5150		
Median	1.425				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

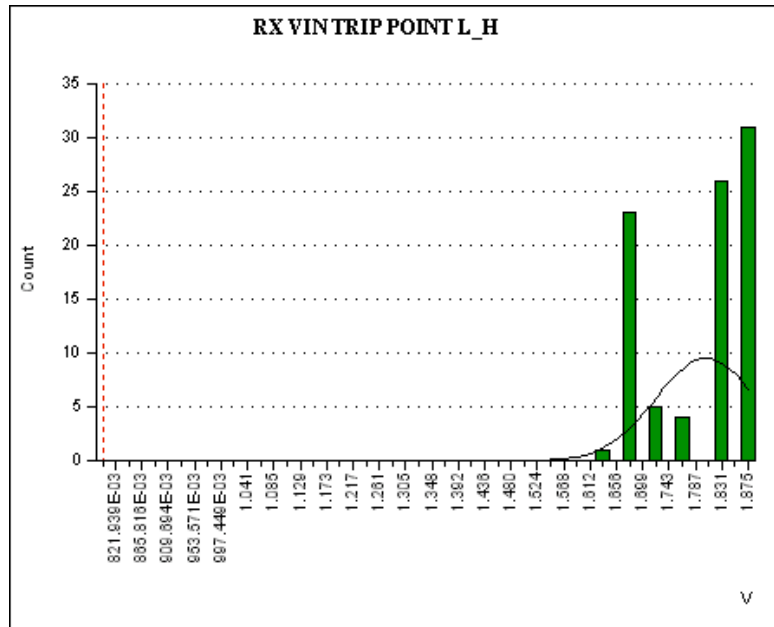
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.003, Test.Name=RX VIN TRIP POINT L_H



Statistics: (V)

Max	1.875	25%	1.675	SpecHigh	N/A
Mean	1.794	10%	1.675	SpecLow	800.000E-03
Min	1.625	N	90	PctWithinSpec	100.00
Range	250.000E-03	Cp	N/A	c	
StdDev	82.645E-03	Cpl	>4.0000	PctDefSpec	0
W	0.7906	Cpu	N/A	NWithinSpec	90
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	1.875	Skew	-0.5660		
75%	1.875	Kurtosis	-1.3292		
Median	1.825				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

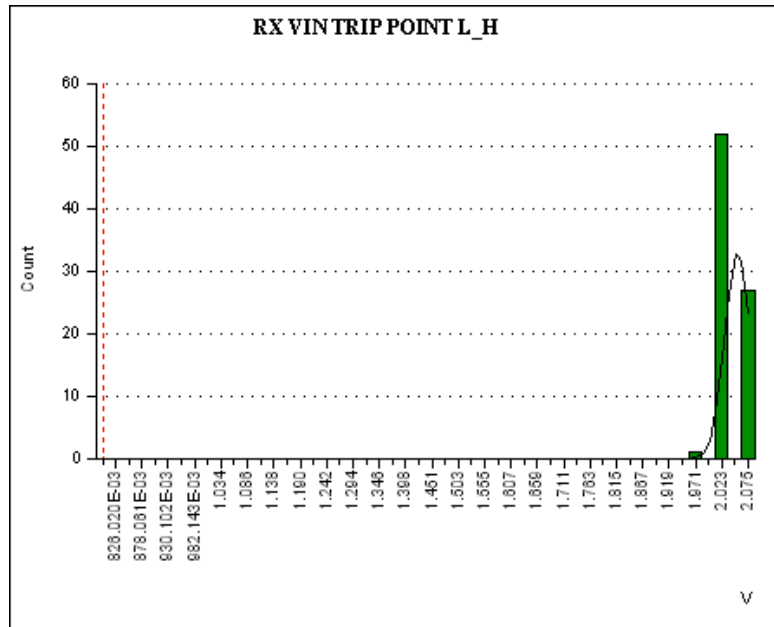
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=13.003, Test.Name=RX VIN TRIP POINT L_H



Statistics: (V)

Max	2.075	25%	2.025	SpecHigh	N/A
Mean	2.041	10%	2.025	SpecLow	800.000E-03
Min	1.975	N	80	PctWithinSpec	100.00
Range	100.000E-03	Cp	N/A	c	
StdDev	24.873E-03	Cpl	>4.0000	PctDefSpec	0
W	0.6496	Cpu	N/A	NWithinSpec	80
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	2.075	Skew	0.4421		
75%	2.075	Kurtosis	-1.0507		
Median	2.025				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

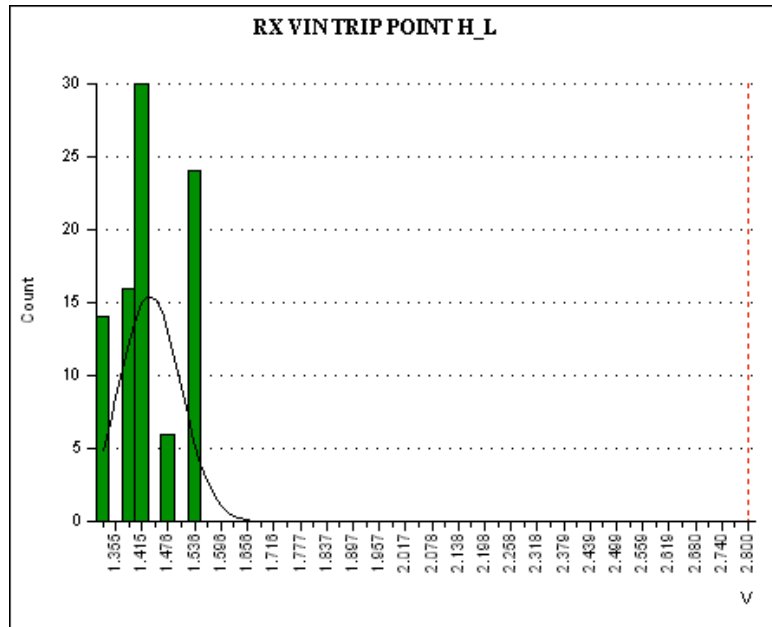
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.004, Test.Name=RX VIN TRIP POINT H_L



Statistics: (V)

Max	1.525	25%	1.375	SpecHigh	2.800
Mean	1.431	10%	1.325	SpecLow	N/A
Min	1.325	N	90	PctWithinSpec	100.00
Range	200.000E-03	Cp	N/A	c	
StdDev	69.688E-03	Cpl	N/A	PctDefSpec	0
W	0.8722	Cpu	>4.0000	NWithinSpec	90
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	1.525	Skew	0.0520		
75%	1.525	Kurtosis	-1.1553		
Median	1.425				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

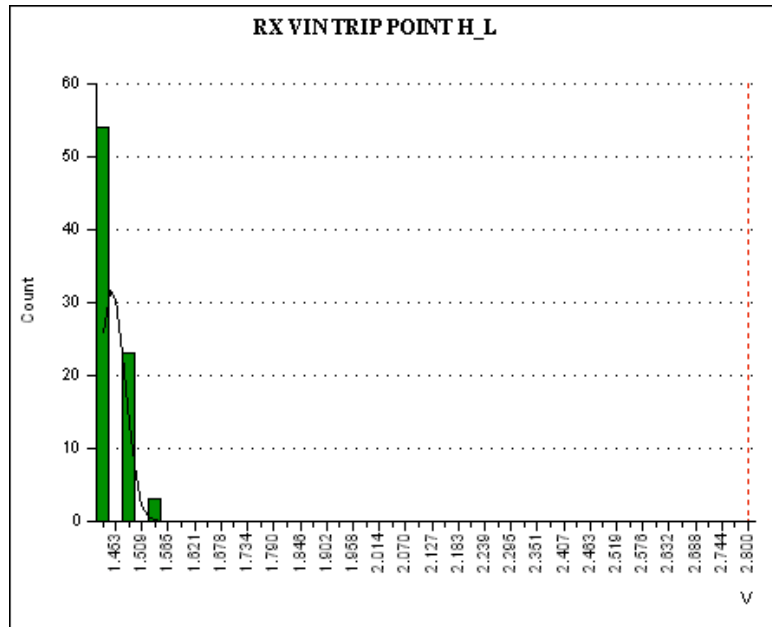
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=13.004, Test.Name=RX VIN TRIP POINT H_L



Statistics: (V)

Max	1.525	25%	1.425	SpecHigh	2.800
Mean	1.443	10%	1.425	SpecLow	N/A
Min	1.425	N	80	PctWithinSpec	100.00
Range	100.000E-03	Cp	N/A	c	
StdDev	27.838E-03	Cpl	N/A	PctDefSpec	0
W	0.6387	Cpu	>4.0000	NWithinSpec	80
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	1.475	Skew	1.2457		
75%	1.475	Kurtosis	0.6212		
Median	1.425				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

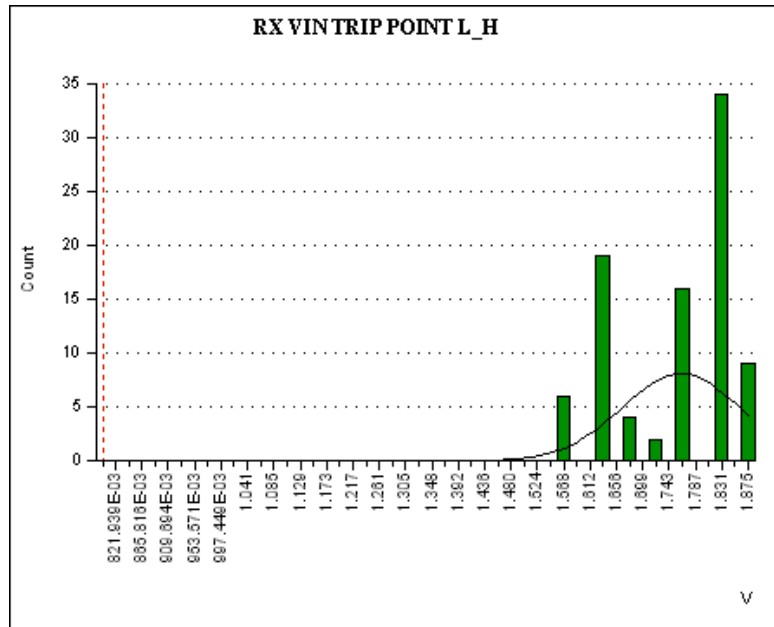
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.006, Test.Name=RX VIN TRIP POINT L_H



Statistics: (V)

Max	1.875	25%	1.625	SpecHigh	N/A
Mean	1.753	10%	1.625	SpecLow	800.000E-03
Min	1.575	N	90	PctWithinSpec	100.00
Range	299.999E-03	Cp	N/A	c	
StdDev	97.454E-03	Cpl	3.2608	PctDefSpec	0
W	0.8296	Cpu	N/A	NWithinSpec	90
WpValue	0.0000	Cpk	3.2608	NOutsideSpec	0
90%	1.850	Skew	-0.5869		
75%	1.825	Kurtosis	-1.2053		
Median	1.775				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

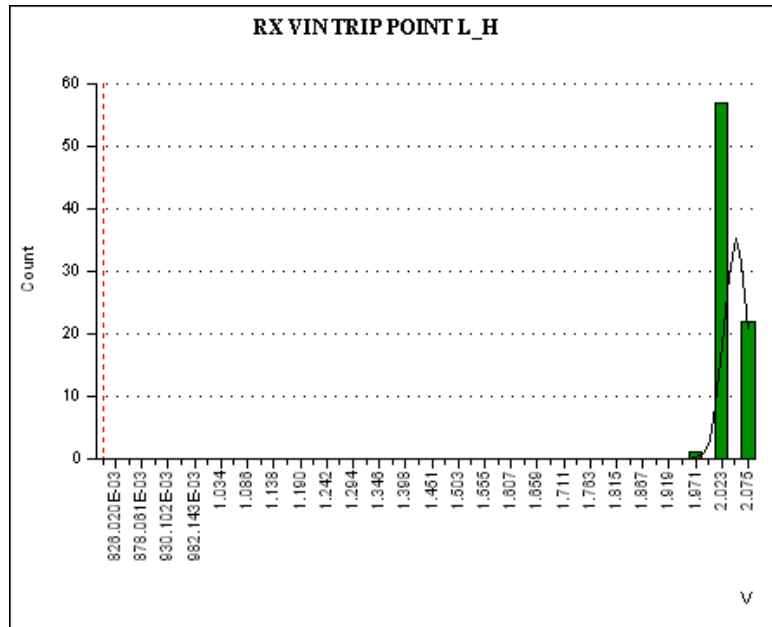
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=13.006, Test.Name=RX VIN TRIP POINT L_H



Statistics: (V)

Max	2.075	25%	2.025	SpecHigh	N/A
Mean	2.038	10%	2.025	SpecLow	800.000E-03
Min	1.975	N	80	PctWithinSpec	100.00
Range	100.000E-03	Cp	N/A	c	
StdDev	23.525E-03	Cpl	>4.0000	PctDefSpec	0
W	0.6153	Cpu	N/A	NWithinSpec	80
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	2.075	Skew	0.7207		
75%	2.075	Kurtosis	-0.5199		
Median	2.025				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

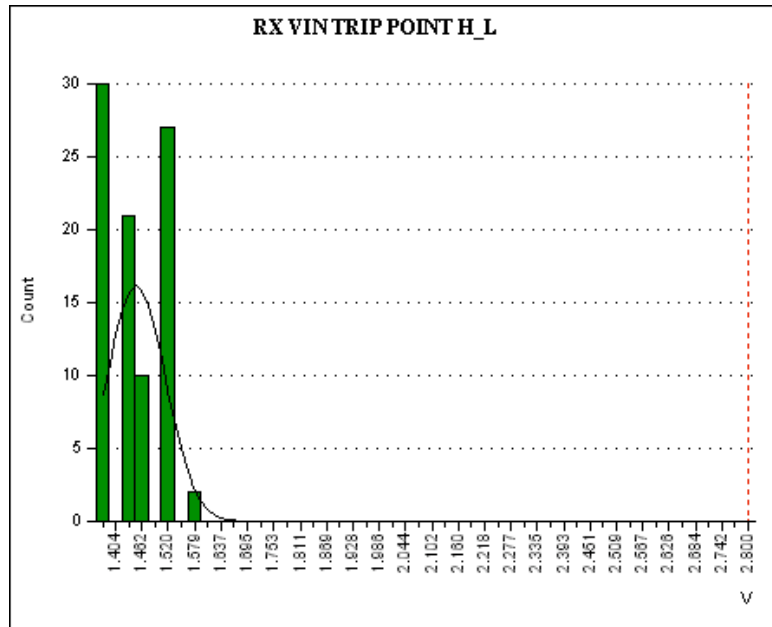
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.007, Test.Name=RX VIN TRIP POINT H_L



Statistics: (V)

Max	1.575	25%	1.375	SpecHigh	2.800
Mean	1.447	10%	1.375	SpecLow	N/A
Min	1.375	N	90	PctWithinSpec	100.00
Range	200.000E-03	Cp	N/A	PctDefSpec	0
StdDev	64.525E-03	Cpl	N/A	NWithinSpec	90
W	0.8298	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	1.525	Skew	0.2378		
75%	1.525	Kurtosis	-1.4755		
Median	1.425				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

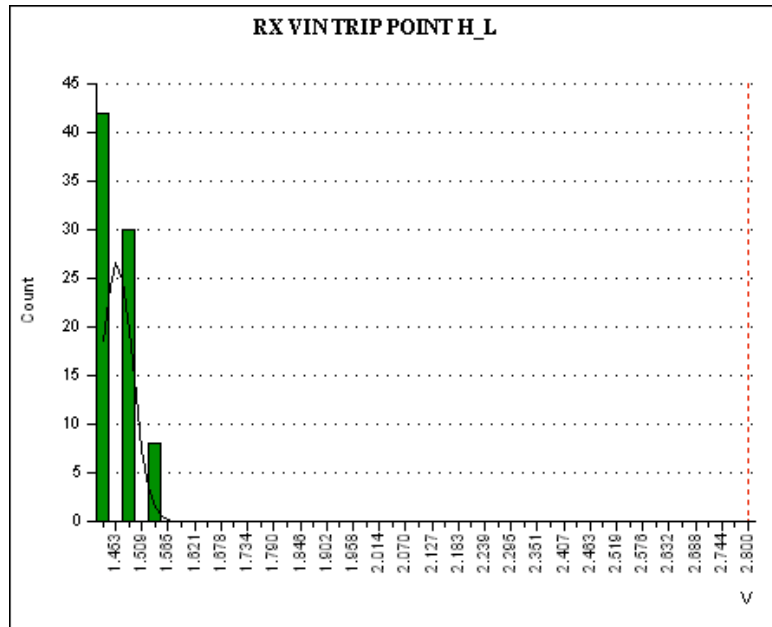
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=13.007, Test.Name=RX VIN TRIP POINT H_L



Statistics: (V)

Max	1.525	25%	1.425	SpecHigh	2.800
Mean	1.454	10%	1.425	SpecLow	N/A
Min	1.425	N	80	PctWithinSpec	100.00
Range	100.000E-03	Cp	N/A	PctDefSpec	0
StdDev	33.541E-03	Cpl	N/A	NWithinSpec	80
W	0.7407	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	1.500	Skew	0.7512		
75%	1.475	Kurtosis	-0.5170		
Median	1.425				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

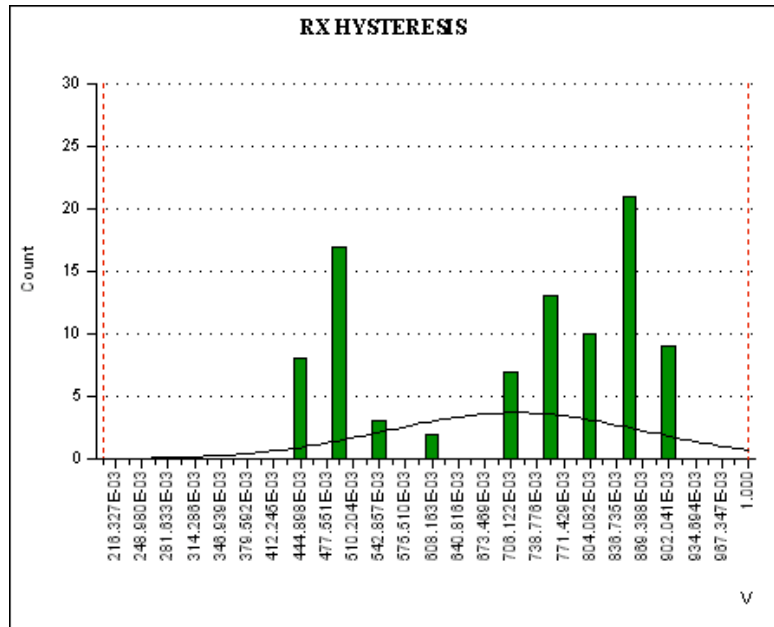
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.008, Test.Name=RX HYSTERESIS



Statistics: (V)

Max	900.000E-03	25%	500.000E-03	SpecHigh	1.000
Mean	706.112E-03	10%	500.000E-03	SpecLow	200.000E-03
Min	450.000E-03	N	90	PctWithinSpec	100.00
Range	450.000E-03	Cp	0.8425	PctDefSpec	0
StdDev	158.261E-03	Cpl	1.0660	NWithinSpec	90
W	0.8487	Cpu	0.6190	NOutsideSpec	0
WpValue	0.0000	Cpk	0.6190		
90%	875.000E-03	Skew	-0.4624		
75%	850.001E-03	Kurtosis	-1.3855		
Median	750.001E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

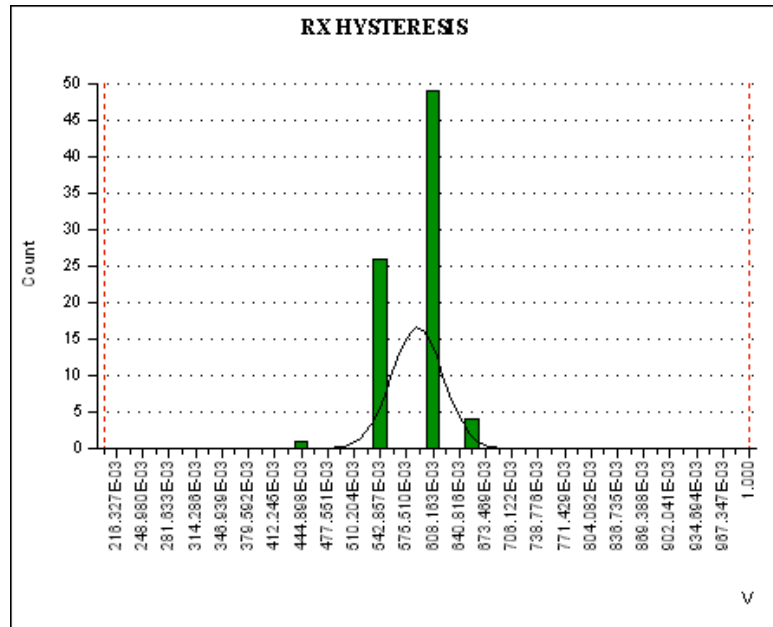
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=13.008, Test.Name=RX HYSTERESIS



Statistics: (V)

Max	650.002E-03	25%	550.001E-03	SpecHigh	1.000
Mean	584.376E-03	10%	550.001E-03	SpecLow	200.000E-03
Min	450.001E-03	N	80	PctWithinSpec	100.00
Range	200.001E-03	Cp	>4.0000	c	
StdDev	31.416E-03	Cpl	>4.0000	PctDefSpec	0
W	0.7345	Cpu	>4.0000	NWithinSpec	80
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	600.001E-03	Skew	-0.9066		
75%	600.001E-03	Kurtosis	3.0442		
Median	600.001E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

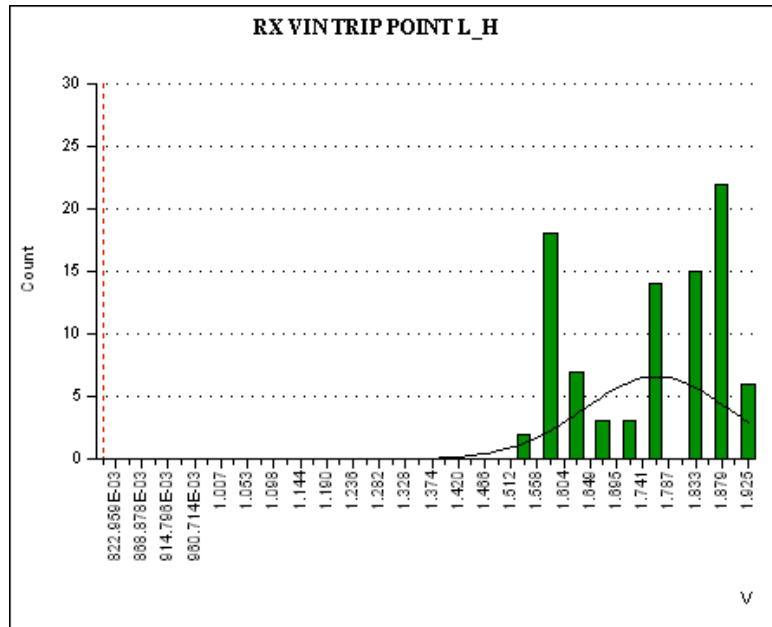
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.009, Test.Name=RX VIN TRIP POINT L_H



Statistics: (V)

Max	1.925	25%	1.625	SpecHigh	N/A
Mean	1.756	10%	1.575	SpecLow	800.000E-03
Min	1.525	N	90	PctWithinSpec	100.00
Range	400.000E-03	Cp	N/A	c	
StdDev	125.352E-03	Cpl	2.5410	PctDefSpec	0
W	0.8659	Cpu	N/A	NWithinSpec	90
WpValue	0.0000	Cpk	2.5410	NOutsideSpec	0
90%	1.875	Skew	-0.4427		
75%	1.875	Kurtosis	-1.3163		
Median	1.775				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

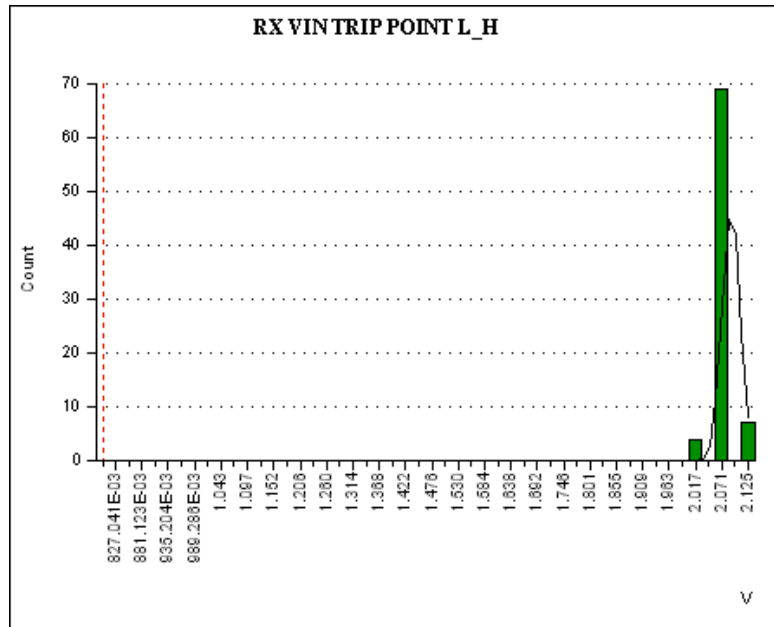
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=13.009, Test.Name=RX VIN TRIP POINT L_H



Statistics: (V)

Max	2.125	25%	2.075	SpecHigh	N/A
Mean	2.077	10%	2.075	SpecLow	800.000E-03
Min	2.025	N	80	PctWithinSpec	100.00
Range	100.000E-03	Cp	N/A	c	
StdDev	18.562E-03	Cpl	>4.0000	PctDefSpec	0
W	0.5071	Cpu	N/A	NWithinSpec	80
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	2.075	Skew	0.4494		
75%	2.075	Kurtosis	4.5350		
Median	2.075				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

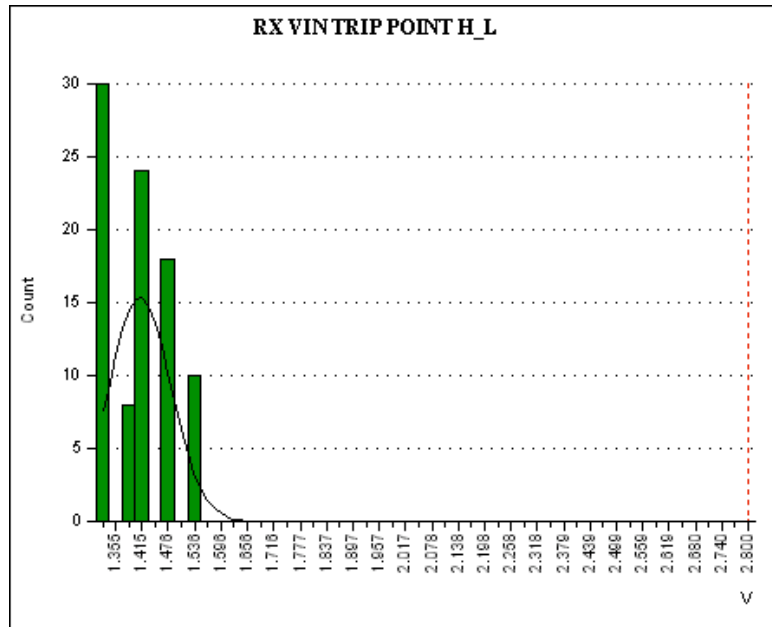
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.010, Test.Name=RX VIN TRIP POINT H_L



Statistics: (V)

Max	1.525	25%	1.325	SpecHigh	2.800
Mean	1.408	10%	1.325	SpecLow	N/A
Min	1.325	N	90	PctWithinSpec	100.00
Range	200.000E-03	Cp	N/A	PctDefSpec	0
StdDev	70.312E-03	Cpl	N/A	NWithinSpec	90
W	0.8609	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	1.525	Skew	0.1212		
75%	1.475	Kurtosis	-1.3007		
Median	1.425				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

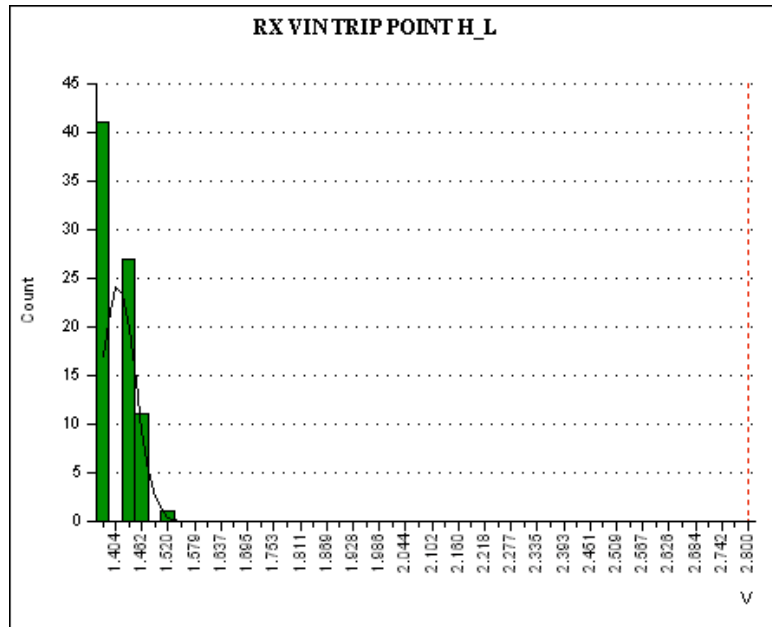
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=13.010, Test.Name=RX VIN TRIP POINT H_L



Statistics: (V)

Max	1.525	25%	1.375	SpecHigh	2.800
Mean	1.407	10%	1.375	SpecLow	N/A
Min	1.375	N	80	PctWithinSpec	100.00
Range	150.001E-03	Cp	N/A	c	
StdDev	38.237E-03	Cpl	N/A	PctDefSpec	0
W	0.7658	Cpu	>4.0000	NWithinSpec	80
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	1.475	Skew	0.8692		
75%	1.425	Kurtosis	-0.1320		
Median	1.375				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

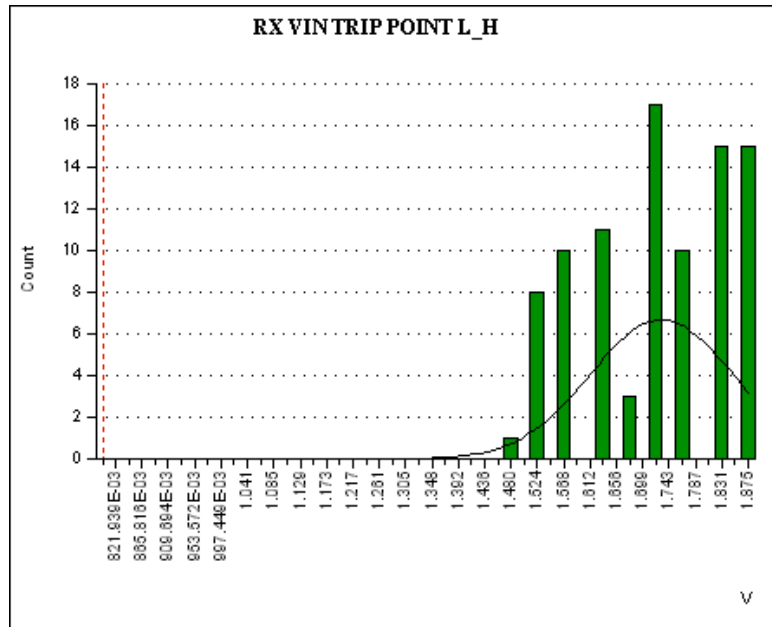
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.012, Test.Name=RX VIN TRIP POINT L_H



Statistics: (V)

Max	1.875	25%	1.625	SpecHigh	N/A
Mean	1.721	10%	1.550	SpecLow	800.000E-03
Min	1.475	N	90	PctWithinSpec	100.00
Range	400.001E-03	Cp	N/A	PctDefSpec	0
StdDev	117.853E-03	Cpl	2.6053	NWithinSpec	90
W	0.9156	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	2.6053		
90%	1.875	Skew	-0.3050		
75%	1.825	Kurtosis	-1.1564		
Median	1.725				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

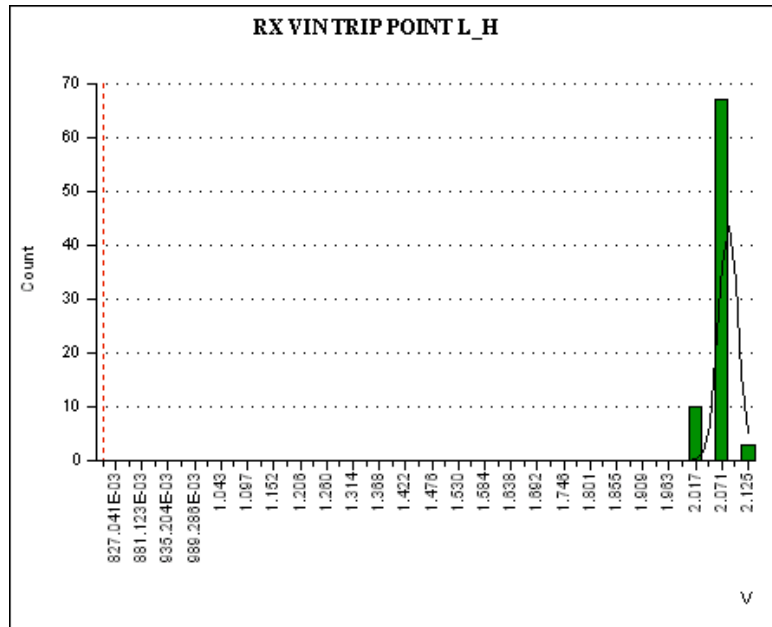
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=13.012, Test.Name=RX VIN TRIP POINT L_H



Statistics: (V)

Max	2.125	25%	2.075	SpecHigh	N/A
Mean	2.071	10%	2.025	SpecLow	800.000E-03
Min	2.025	N	80	PctWithinSpec	100.00
Range	100.000E-03	Cp	N/A	c	
StdDev	19.799E-03	Cpl	>4.0000	PctDefSpec	0
W	0.5364	Cpu	N/A	NWithinSpec	80
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	2.075	Skew	-0.7725		
75%	2.075	Kurtosis	3.0666		
Median	2.075				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

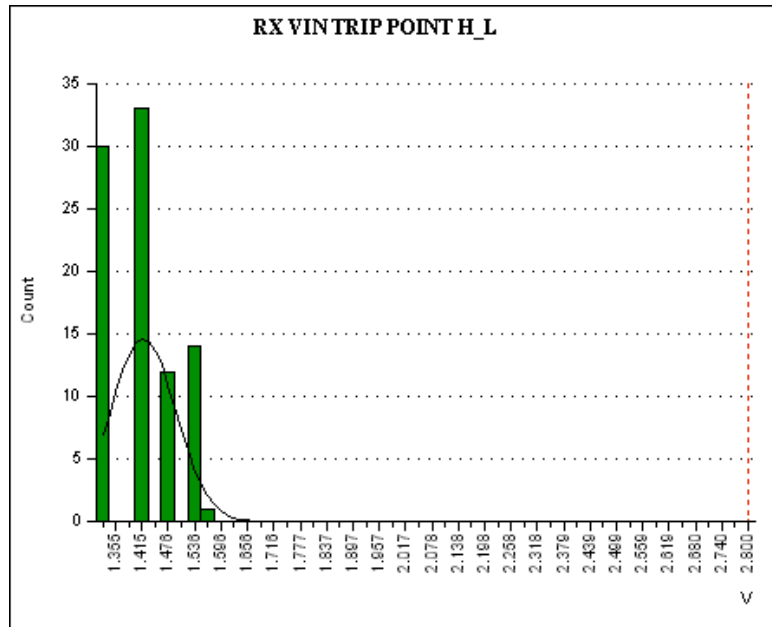
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.013, Test.Name=RX VIN TRIP POINT H_L



Statistics: (V)

Max	1.575	25%	1.325	SpecHigh	2.800
Mean	1.416	10%	1.325	SpecLow	N/A
Min	1.325	N	90	PctWithinSpec	100.00
Range	250.000E-03	Cp	N/A	PctDefSpec	0
StdDev	73.780E-03	Cpl	N/A	NWithinSpec	90
W	0.8520	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	1.525	Skew	0.0766		
75%	1.475	Kurtosis	-1.1477		
Median	1.425				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

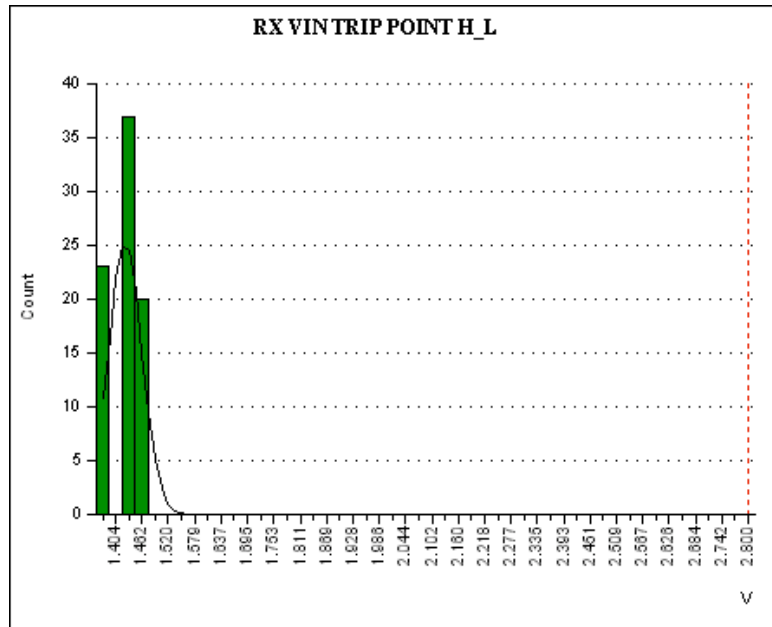
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=13.013, Test.Name=RX VIN TRIP POINT H_L



Statistics: (V)

Max	1.475	25%	1.375	SpecHigh	2.800
Mean	1.423	10%	1.375	SpecLow	N/A
Min	1.375	N	80	PctWithinSpec	100.00
Range	100.000E-03	Cp	N/A	PctDefSpec	0
StdDev	36.840E-03	Cpl	N/A	NWithinSpec	80
W	0.8091	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	1.475	Skew	0.0594		
75%	1.450	Kurtosis	-1.1288		
Median	1.425				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

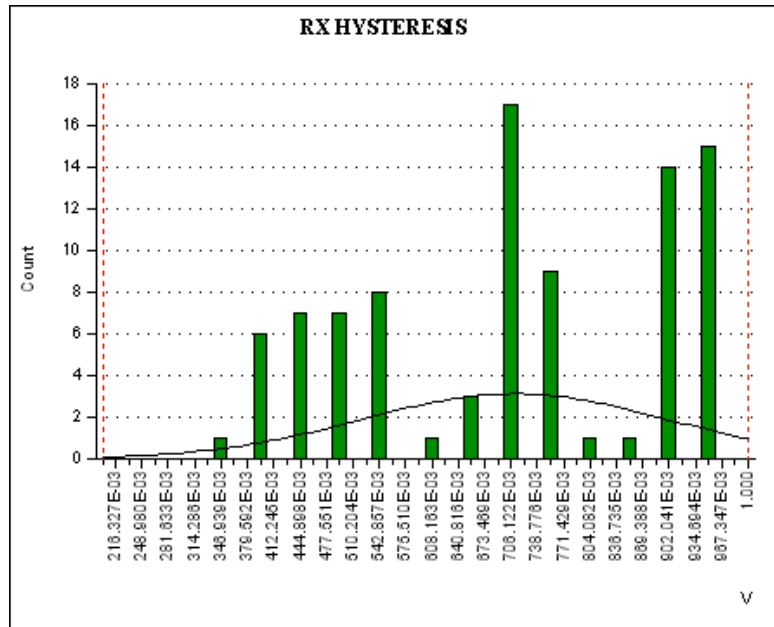
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.014, Test.Name=RX HYSTERESIS



Statistics: (V)

Max	950.001E-03	25%	550.002E-03	SpecHigh	1.000
Mean	705.557E-03	10%	450.001E-03	SpecLow	200.000E-03
Min	350.001E-03	N	90	PctWithinSpec	100.00
Range	600.000E-03	Cp	0.7113	PctDefSpec	0
StdDev	187.449E-03	Cpl	0.8990	NWithinSpec	90
W	0.9088	Cpu	0.5236	NOutsideSpec	0
WpValue	0.0000	Cpk	0.5236		
90%	950.001E-03	Skew	-0.1725		
75%	900.001E-03	Kurtosis	-1.2581		
Median	700.001E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

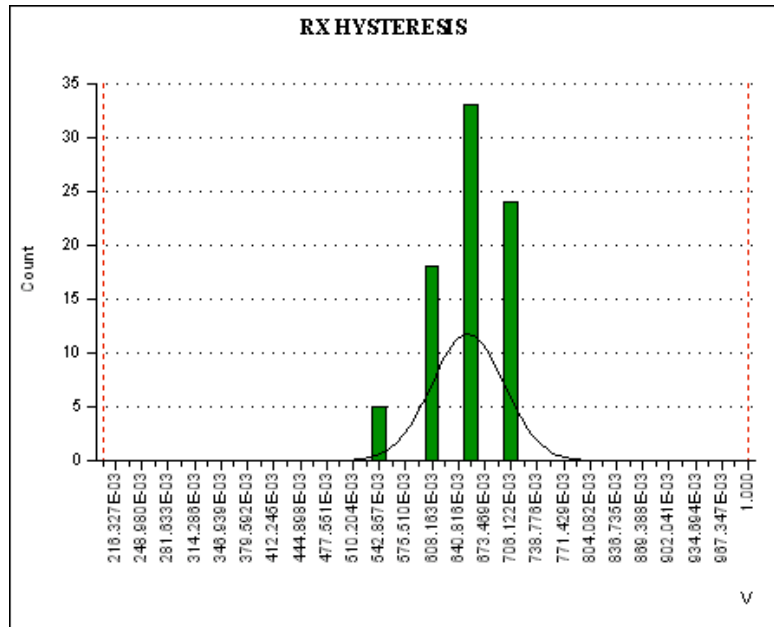
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=13.014, Test.Name=RX HYSTERESIS



Statistics: (V)

Max	700.002E-03	25%	600.001E-03	SpecHigh	1.000
Mean	647.502E-03	10%	600.001E-03	SpecLow	200.000E-03
Min	550.001E-03	N	80	PctWithinSpec	100.00
Range	150.001E-03	Cp	3.0150	c	
StdDev	44.223E-03	Cpl	3.3730	PctDefSpec	0
W	0.8530	Cpu	2.6570	NWithinSpec	80
WpValue	0.0000	Cpk	2.6570	NOutsideSpec	0
90%	700.002E-03	Skew	-0.4638		
75%	700.002E-03	Kurtosis	-0.5257		
Median	650.002E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

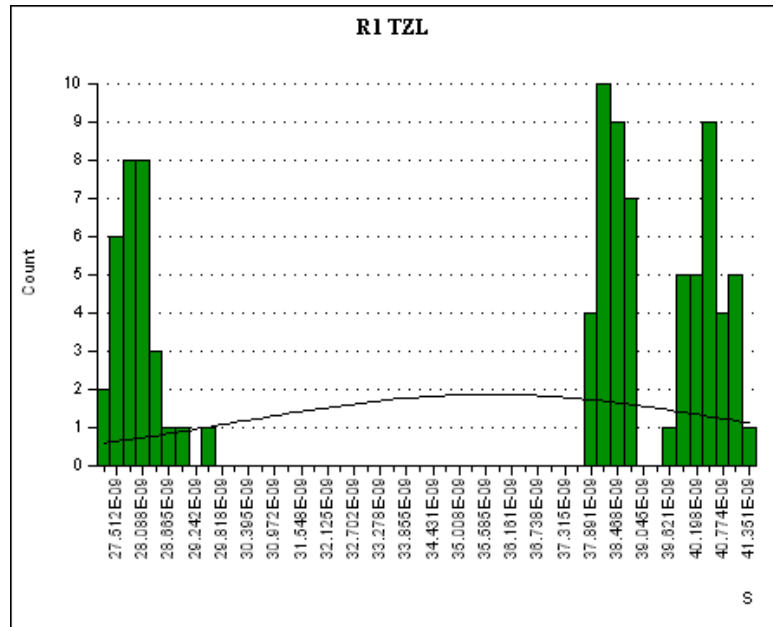
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=14.000, Test.Name=R1 TZL



Statistics: (S)

Max	41.351E-09	25%	28.060E-09	SpecHigh	N/A
Mean	35.602E-09	10%	27.688E-09	SpecLow	N/A
Min	27.223E-09	N	90	PctWithinSpec	N/A
Range	14.128E-09	Cp	N/A	PctDefSpec	N/A
StdDev	5.533E-09	Cpl	N/A	NWithinSpec	N/A
W	0.7390	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	40.701E-09	Skew	-0.6351		
75%	40.236E-09	Kurtosis	-1.4932		
Median	38.382E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

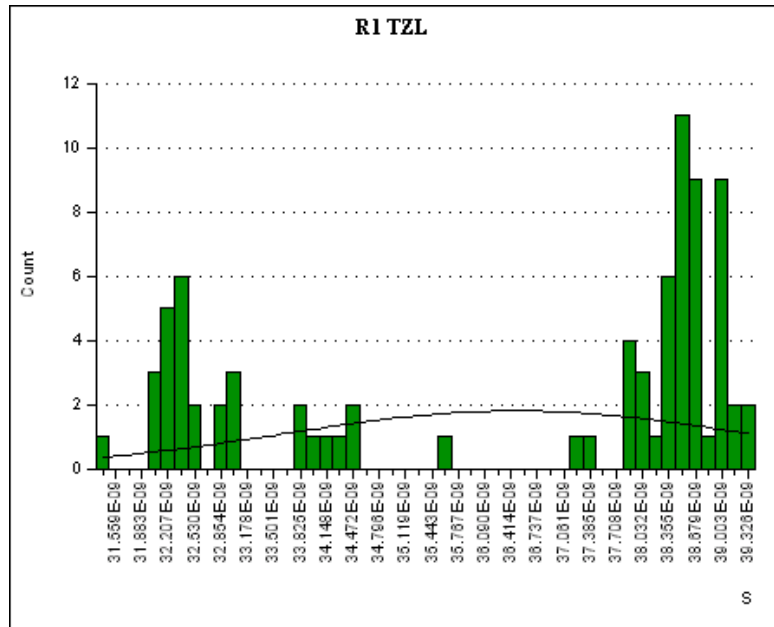
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=14.000, Test.Name=R1 TZL



Statistics: (S)

Max	39.326E-09	25%	33.002E-09	SpecHigh	N/A
Mean	36.432E-09	10%	32.247E-09	SpecLow	N/A
Min	31.398E-09	N	80	PctWithinSpec	N/A
Range	7.929E-09	Cp	N/A	c	
StdDev	2.831E-09	Cpl	N/A	PctDefSpec	N/A
W	0.7702	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	39.043E-09	Skew	-0.5947		
75%	38.666E-09	Kurtosis	-1.4956		
Median	38.241E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

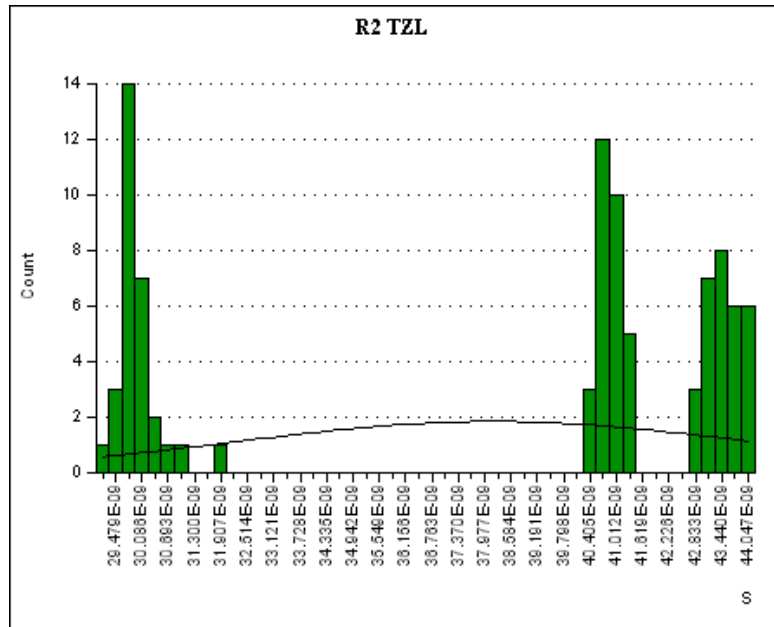
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.001, Test.Name=R2 TZL



Statistics: (S)

Max	44.047E-09	25%	30.105E-09	SpecHigh	N/A
Mean	38.106E-09	10%	29.733E-09	SpecLow	N/A
Min	29.175E-09	N	90	PctWithinSpec	N/A
Range	14.871E-09	Cp	N/A	PctDefSpec	N/A
StdDev	5.891E-09	Cpl	N/A	NWithinSpec	N/A
W	0.7463	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	43.768E-09	Skew	-0.6094		
75%	43.210E-09	Kurtosis	-1.4967		
Median	40.846E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

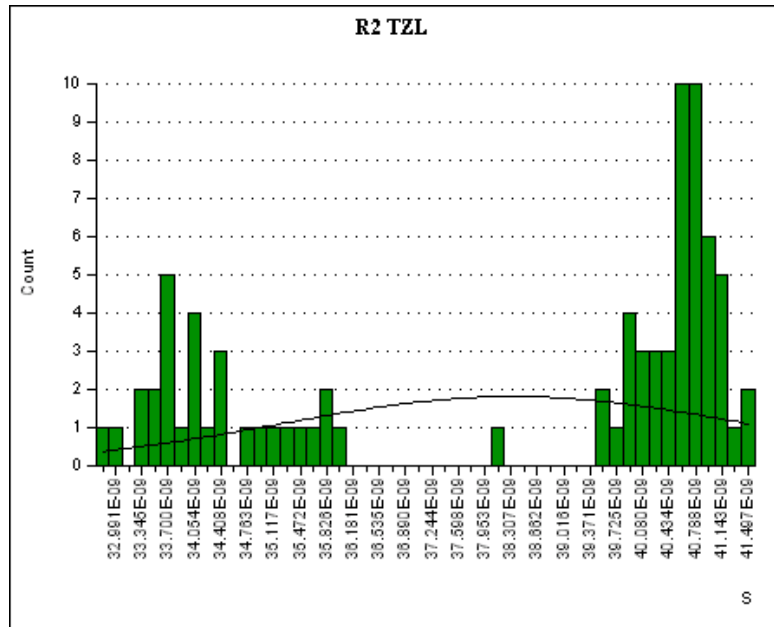
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=14.001, Test.Name=R2 TZL



Statistics: (S)

Max	41.497E-09	25%	34.560E-09	SpecHigh	N/A
Mean	38.295E-09	10%	33.710E-09	SpecLow	N/A
Min	32.813E-09	N	80	PctWithinSpec	N/A
Range	8.684E-09	Cp	N/A	c	
StdDev	3.115E-09	Cpl	N/A	PctDefSpec	N/A
W	0.7706	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	41.073E-09	Skew	-0.6068		
75%	40.742E-09	Kurtosis	-1.4850		
Median	40.176E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

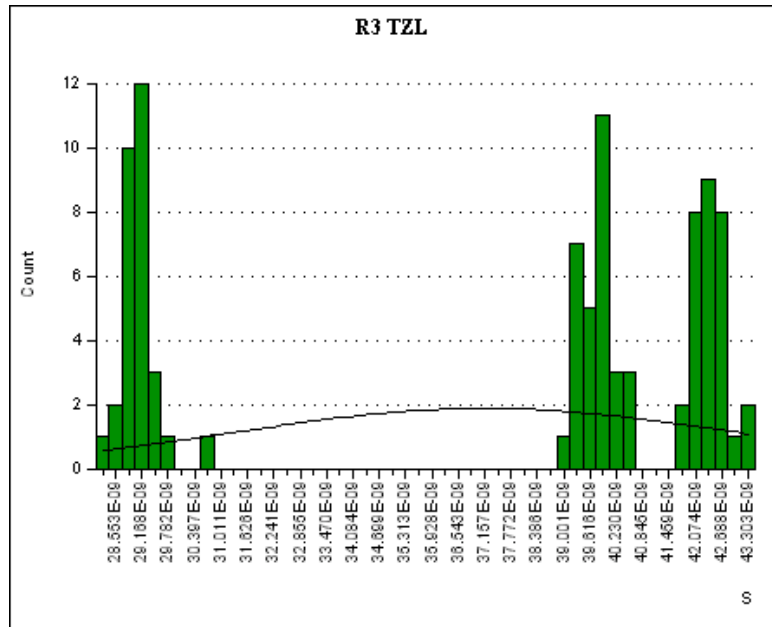
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.002, Test.Name=R3 TZL



Statistics: (S)

Max	43.303E-09	25%	29.175E-09	SpecHigh	N/A
Mean	37.095E-09	10%	28.896E-09	SpecLow	N/A
Min	28.246E-09	N	90	PctWithinSpec	N/A
Range	15.057E-09	Cp	N/A	PctDefSpec	N/A
StdDev	5.810E-09	Cpl	N/A	NWithinSpec	N/A
W	0.7486	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	42.559E-09	Skew	-0.6064		
75%	42.188E-09	Kurtosis	-1.5002		
Median	39.777E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

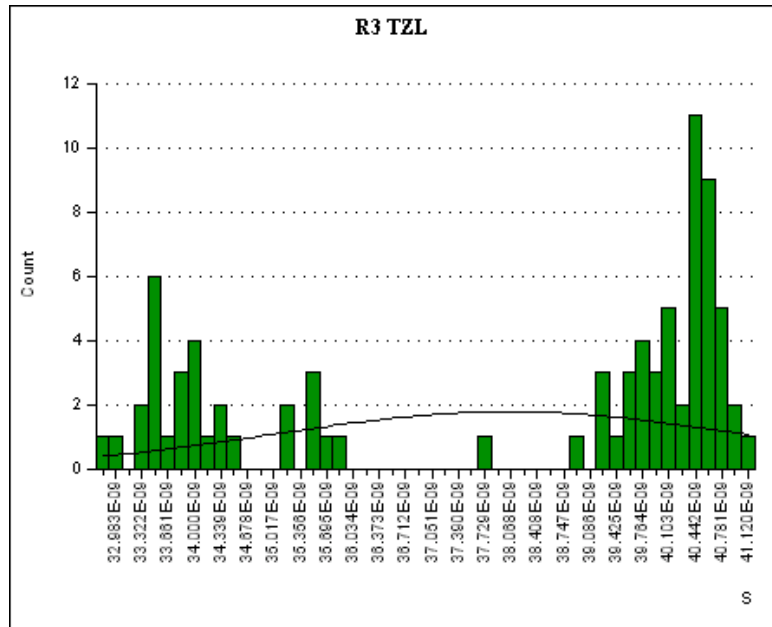
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=14.002, Test.Name=R3 TZL



Statistics: (S)

Max	41.120E-09	25%	34.371E-09	SpecHigh	N/A
Mean	37.998E-09	10%	33.521E-09	SpecLow	N/A
Min	32.813E-09	N	80	PctWithinSpec	N/A
Range	8.306E-09	Cp	N/A	c	
StdDev	3.006E-09	Cpl	N/A	PctDefSpec	N/A
W	0.7727	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	40.695E-09	Skew	-0.5929		
75%	40.459E-09	Kurtosis	-1.4986		
Median	39.798E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

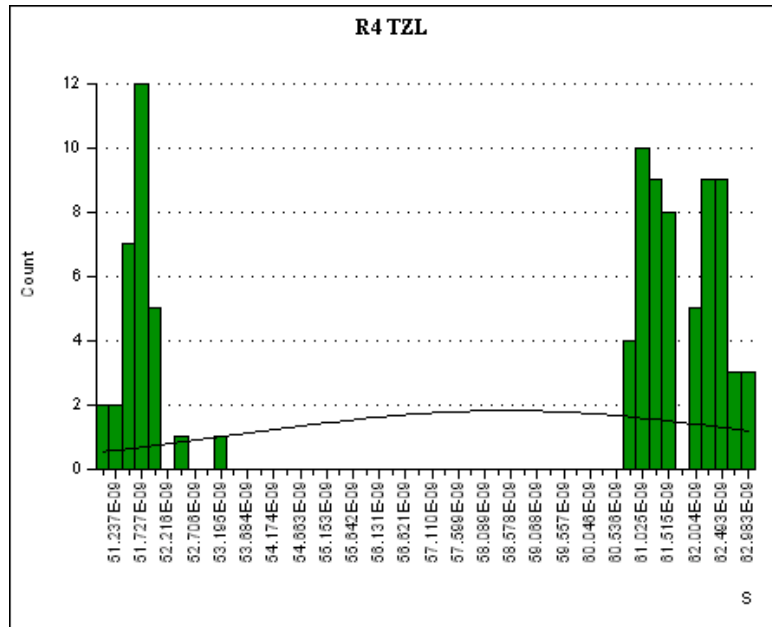
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.003, Test.Name=R4 TZL



Statistics: (S)

Max	62.983E-09	25%	51.829E-09	SpecHigh	N/A
Mean	58.414E-09	10%	51.550E-09	SpecLow	N/A
Min	50.993E-09	N	90	PctWithinSpec	N/A
Range	11.990E-09	Cp	N/A	c	
StdDev	4.806E-09	Cpl	N/A	PctDefSpec	N/A
W	0.7038	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	62.518E-09	Skew	-0.6840		
75%	62.146E-09	Kurtosis	-1.4950		
Median	61.221E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

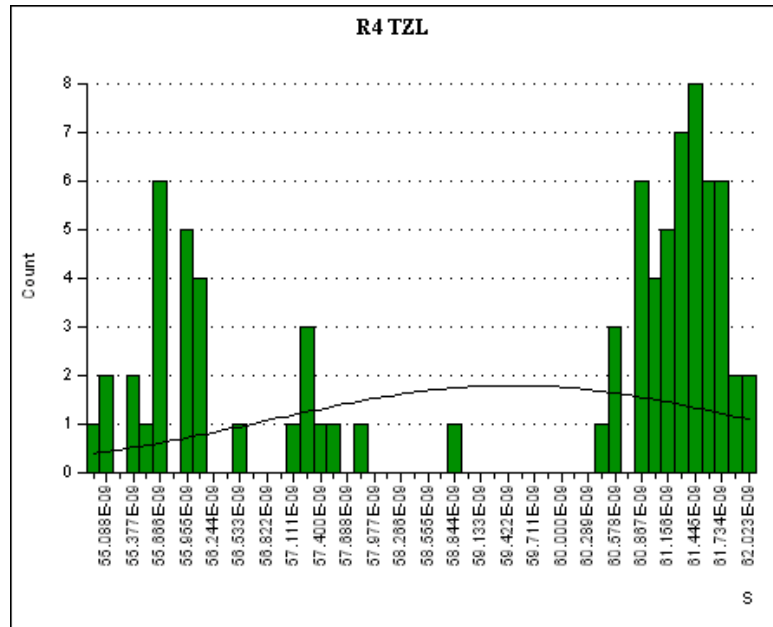
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=14.003, Test.Name=R4 TZL



Statistics: (S)

Max	62.023E-09	25%	56.171E-09	SpecHigh	N/A
Mean	59.409E-09	10%	55.699E-09	SpecLow	N/A
Min	54.943E-09	N	80	PctWithinSpec	N/A
Range	7.079E-09	Cp	N/A	PctDefSpec	N/A
StdDev	2.561E-09	Cpl	N/A	NWithinSpec	N/A
W	0.7702	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	61.740E-09	Skew	-0.6102		
75%	61.456E-09	Kurtosis	-1.4741		
Median	60.937E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

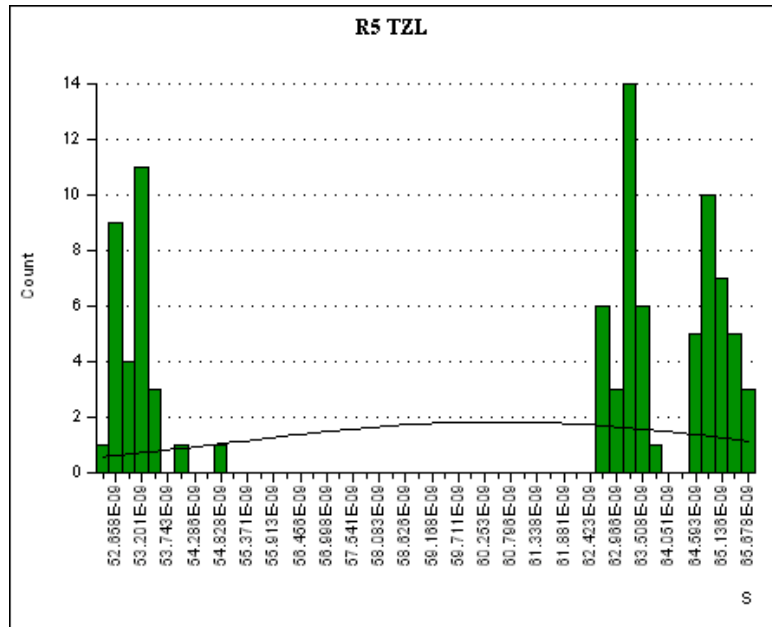
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.004, Test.Name=R5 TZL



Statistics: (S)

Max	65.678E-09	25%	53.223E-09	SpecHigh	N/A
Mean	60.434E-09	10%	52.759E-09	SpecLow	N/A
Min	52.387E-09	N	90	PctWithinSpec	N/A
Range	13.291E-09	Cp	N/A	PctDefSpec	N/A
StdDev	5.289E-09	Cpl	N/A	NWithinSpec	N/A
W	0.7258	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	65.120E-09	Skew	-0.6538		
75%	64.842E-09	Kurtosis	-1.4958		
Median	63.174E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

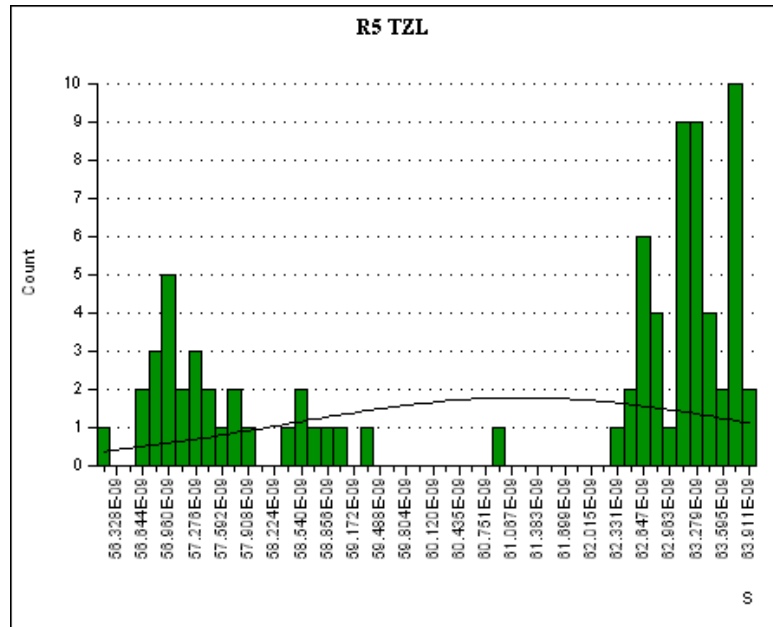
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=14.004, Test.Name=R5 TZL



Statistics: (S)

Max	63.911E-09	25%	57.728E-09	SpecHigh	N/A
Mean	61.130E-09	10%	56.973E-09	SpecLow	N/A
Min	56.171E-09	N	80	PctWithinSpec	N/A
Range	7.740E-09	Cp	N/A	c	
StdDev	2.822E-09	Cpl	N/A	PctDefSpec	N/A
W	0.7685	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	63.722E-09	Skew	-0.6046		
75%	63.344E-09	Kurtosis	-1.4905		
Median	62.778E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

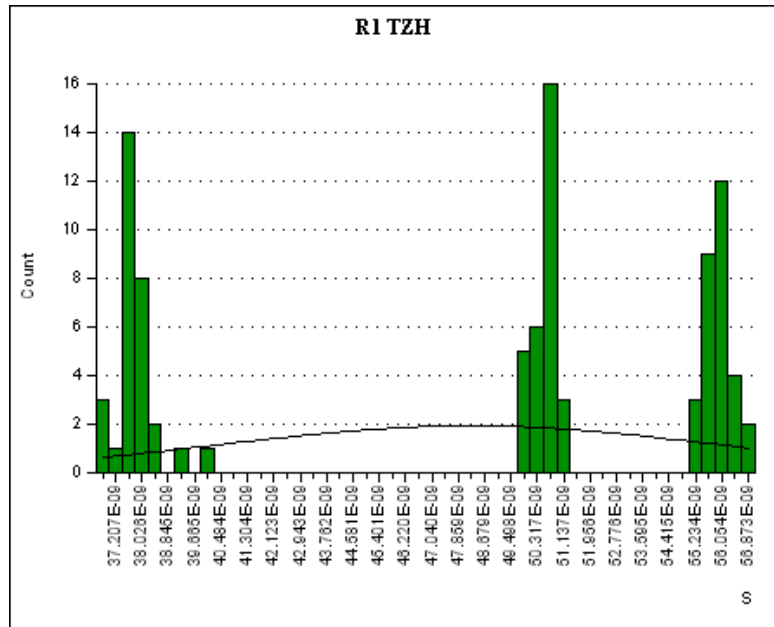
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.005, Test.Name=R1 TZh



Statistics: (S)

Max	56.873E-09	25%	38.005E-09	SpecHigh	N/A
Mean	48.102E-09	10%	37.633E-09	SpecLow	N/A
Min	36.797E-09	N	90	PctWithinSpec	N/A
Range	20.076E-09	Cp	N/A	PctDefSpec	N/A
StdDev	7.613E-09	Cpl	N/A	NWithinSpec	N/A
W	0.7910	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	55.990E-09	Skew	-0.4628		
75%	55.572E-09	Kurtosis	-1.4976		
Median	50.562E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

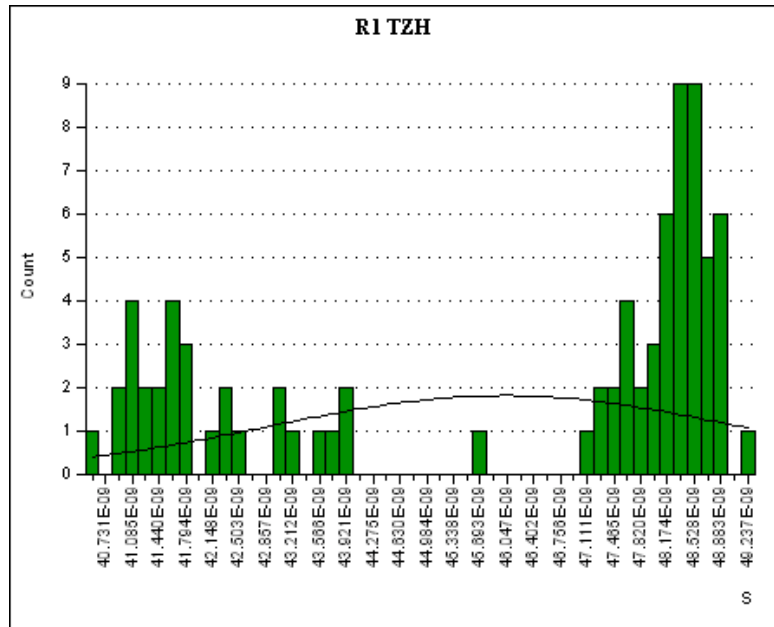
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=14.005, Test.Name=R1 TZh



Statistics: (S)

Max	49.237E-09	25%	42.300E-09	SpecHigh	N/A
Mean	45.960E-09	10%	41.261E-09	SpecLow	N/A
Min	40.553E-09	N	80	PctWithinSpec	N/A
Range	8.684E-09	Cp	N/A	PctDefSpec	N/A
StdDev	3.107E-09	Cpl	N/A	NWithinSpec	N/A
W	0.7709	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	48.671E-09	Skew	-0.6156		
75%	48.482E-09	Kurtosis	-1.4644		
Median	47.821E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

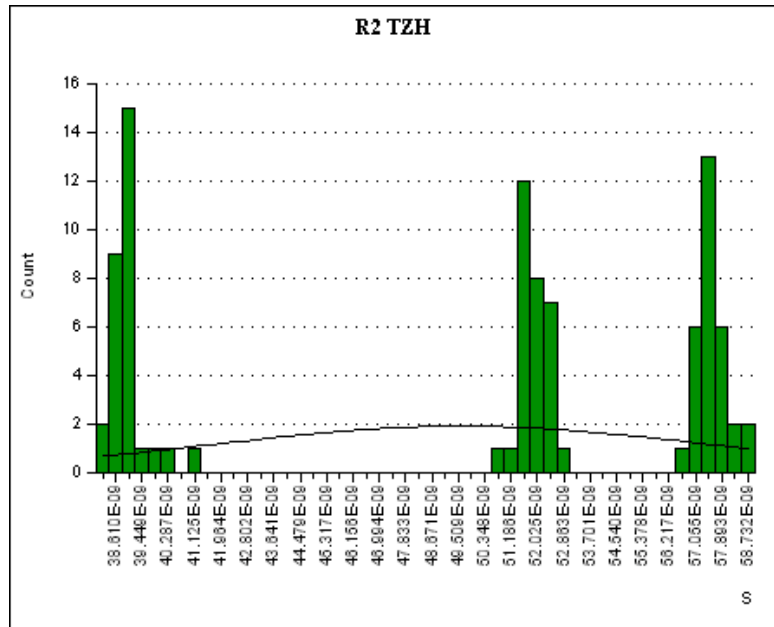
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.006, Test.Name=R2 TZh



Statistics: (S)

Max	58.732E-09	25%	39.120E-09	SpecHigh	N/A
Mean	49.493E-09	10%	38.656E-09	SpecLow	N/A
Min	38.191E-09	N	90	PctWithinSpec	N/A
Range	20.541E-09	Cp	N/A	PctDefSpec	N/A
StdDev	7.839E-09	Cpl	N/A	NWithinSpec	N/A
W	0.7953	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	57.802E-09	Skew	-0.4391		
75%	57.338E-09	Kurtosis	-1.5013		
Median	51.864E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

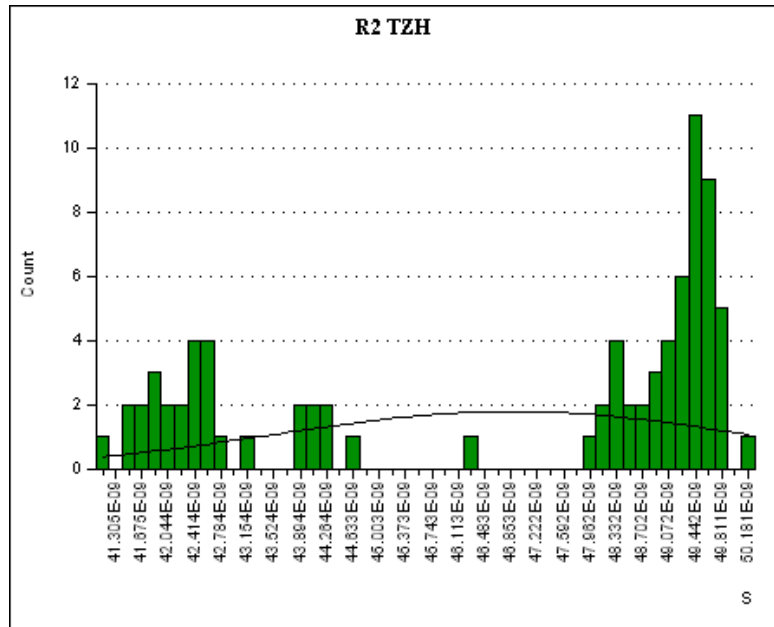
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=14.006, Test.Name=R2 TZh



Statistics: (S)

Max	50.181E-09	25%	42.724E-09	SpecHigh	N/A
Mean	46.799E-09	10%	41.922E-09	SpecLow	N/A
Min	41.120E-09	N	80	PctWithinSpec	N/A
Range	9.061E-09	Cp	N/A	PctDefSpec	N/A
StdDev	3.265E-09	Cpl	N/A	NWithinSpec	N/A
W	0.7707	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	49.709E-09	Skew	-0.6056		
75%	49.473E-09	Kurtosis	-1.4761		
Median	48.671E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

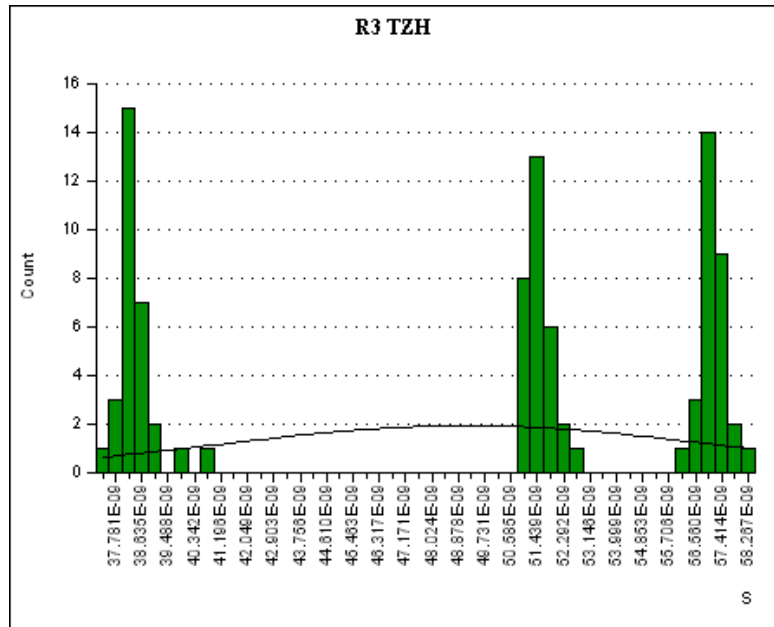
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.007, Test.Name=R3 TZh



Statistics: (S)

Max	58.267E-09	25%	38.749E-09	SpecHigh	N/A
Mean	49.029E-09	10%	38.098E-09	SpecLow	N/A
Min	37.354E-09	N	90	PctWithinSpec	N/A
Range	20.913E-09	Cp	N/A	PctDefSpec	N/A
StdDev	7.895E-09	Cpl	N/A	NWithinSpec	N/A
W	0.7917	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	57.338E-09	Skew	-0.4572		
75%	56.873E-09	Kurtosis	-1.5001		
Median	51.492E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

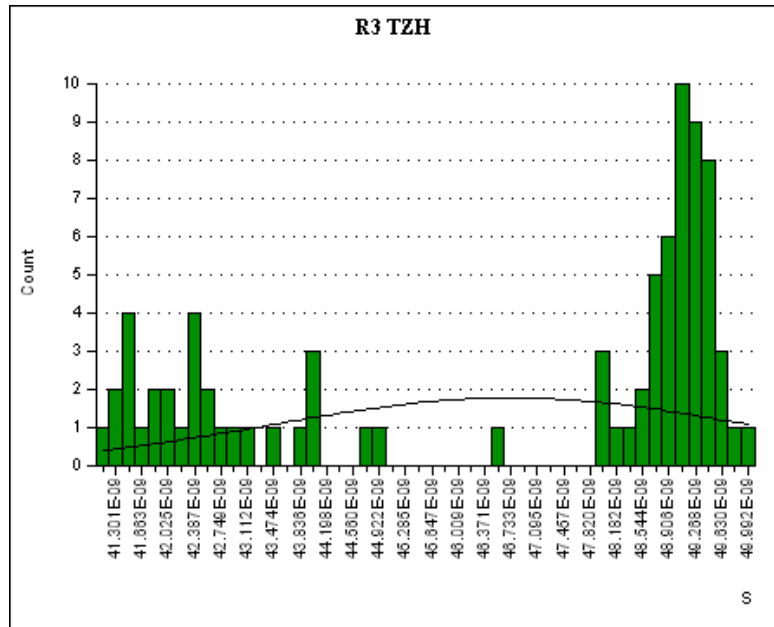
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=14.007, Test.Name=R3 TZh



Statistics: (S)

Max	49.992E-09	25%	42.866E-09	SpecHigh	N/A
Mean	46.677E-09	10%	41.686E-09	SpecLow	N/A
Min	41.120E-09	N	80	PctWithinSpec	N/A
Range	8.873E-09	Cp	N/A	c	
StdDev	3.239E-09	Cpl	N/A	PctDefSpec	N/A
W	0.7658	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	49.521E-09	Skew	-0.6362		
75%	49.237E-09	Kurtosis	-1.4355		
Median	48.765E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

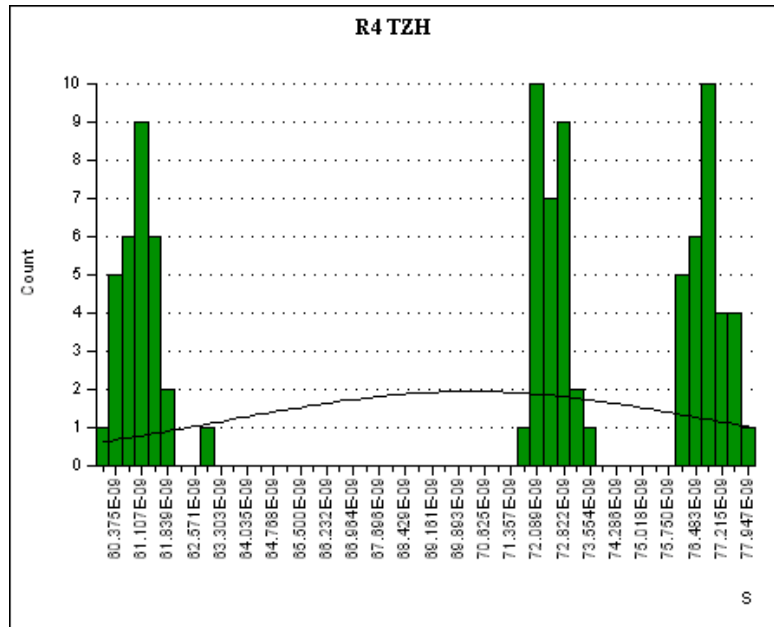
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.008, Test.Name=R4 TZh



Statistics: (S)

Max	77.947E-09	25%	61.310E-09	SpecHigh	N/A
Mean	70.129E-09	10%	60.752E-09	SpecLow	N/A
Min	60.008E-09	N	90	PctWithinSpec	N/A
Range	17.938E-09	Cp	N/A	c	
StdDev	6.748E-09	Cpl	N/A	PctDefSpec	N/A
W	0.7926	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	77.064E-09	Skew	-0.4897		
75%	76.553E-09	Kurtosis	-1.4948		
Median	72.471E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

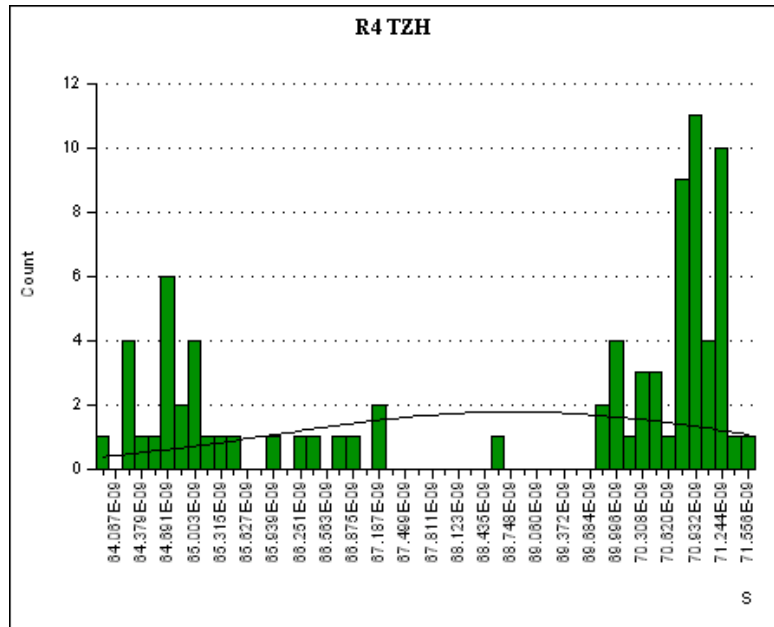
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=14.008, Test.Name=R4 TZh



Statistics: (S)

Max	71.556E-09	25%	65.279E-09	SpecHigh	N/A
Mean	68.722E-09	10%	64.666E-09	SpecLow	N/A
Min	63.911E-09	N	80	PctWithinSpec	N/A
Range	7.646E-09	Cp	N/A	c	
StdDev	2.773E-09	Cpl	N/A	PctDefSpec	N/A
W	0.7663	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	71.179E-09	Skew	-0.6282		
75%	70.895E-09	Kurtosis	-1.4497		
Median	70.376E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

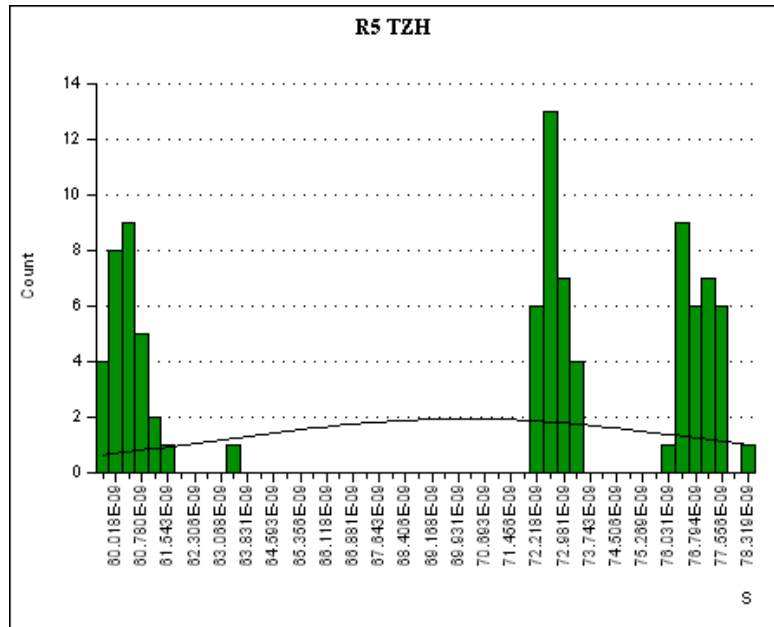
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.009, Test.Name=R5 TZh



Statistics: (S)

Max	78.319E-09	25%	60.659E-09	SpecHigh	N/A
Mean	70.035E-09	10%	60.101E-09	SpecLow	N/A
Min	59.637E-09	N	90	PctWithinSpec	N/A
Range	18.682E-09	Cp	N/A	PctDefSpec	N/A
StdDev	7.043E-09	Cpl	N/A	NWithinSpec	N/A
W	0.7804	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	77.203E-09	Skew	-0.5313		
75%	76.553E-09	Kurtosis	-1.4889		
Median	72.750E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

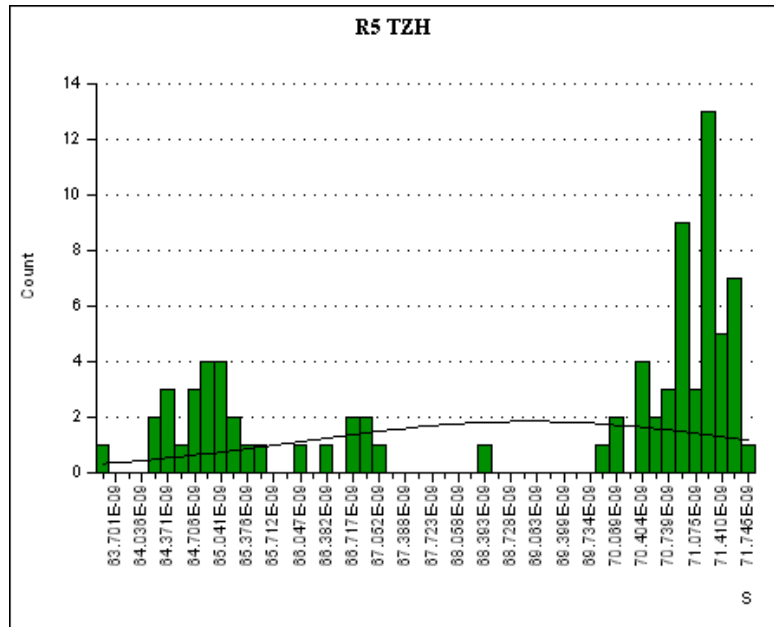
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=14.009, Test.Name=R5 TZh



Statistics: (S)

Max	71.745E-09	25%	65.279E-09	SpecHigh	N/A
Mean	68.907E-09	10%	64.666E-09	SpecLow	N/A
Min	63.533E-09	N	80	PctWithinSpec	N/A
Range	8.212E-09	Cp	N/A	PctDefSpec	N/A
StdDev	2.890E-09	Cpl	N/A	NWithinSpec	N/A
W	0.7683	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	71.509E-09	Skew	-0.6221		
75%	71.179E-09	Kurtosis	-1.4534		
Median	70.754E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

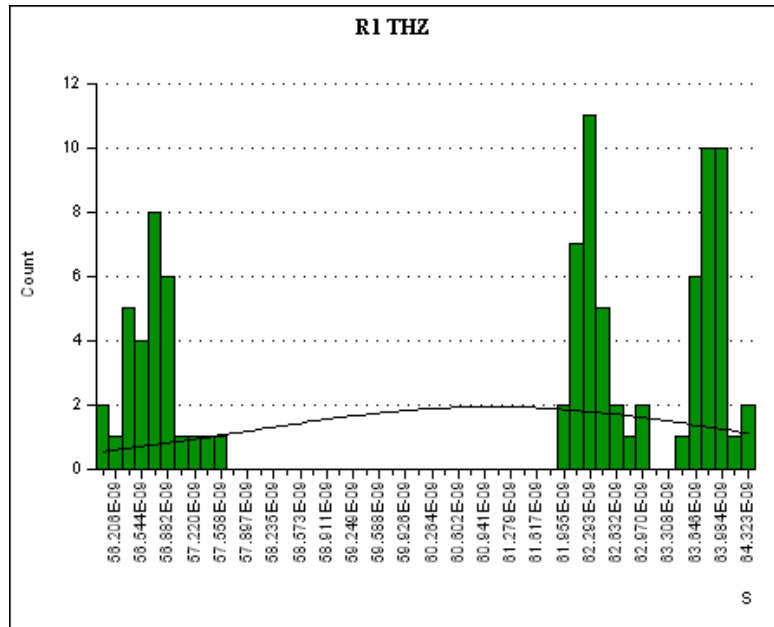
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.010, Test.Name=R1 THZ



Statistics: (S)

Max	64.323E-09	25%	56.873E-09	SpecHigh	N/A
Mean	60.974E-09	10%	56.548E-09	SpecLow	N/A
Min	56.036E-09	N	90	PctWithinSpec	N/A
Range	8.286E-09	Cp	N/A	PctDefSpec	N/A
StdDev	3.117E-09	Cpl	N/A	NWithinSpec	N/A
W	0.7696	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	63.997E-09	Skew	-0.5954		
75%	63.765E-09	Kurtosis	-1.4791		
Median	62.264E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

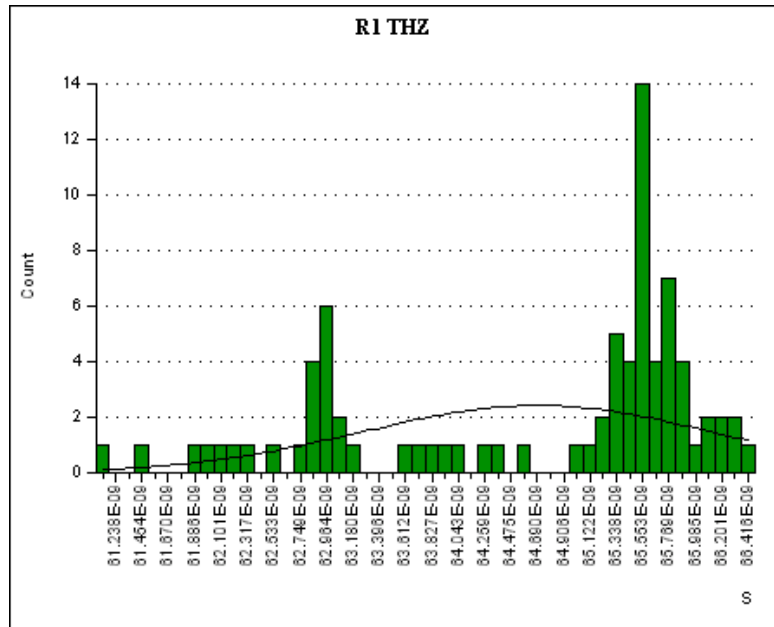
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=14.010, Test.Name=R1 THZ



Statistics: (S)

Max	66.416E-09	25%	63.113E-09	SpecHigh	N/A
Mean	64.654E-09	10%	62.641E-09	SpecLow	N/A
Min	61.130E-09	N	80	PctWithinSpec	N/A
Range	5.286E-09	Cp	N/A	c	
StdDev	1.418E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8466	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	65.897E-09	Skew	-0.8108		
75%	65.661E-09	Kurtosis	-0.7317		
Median	65.472E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

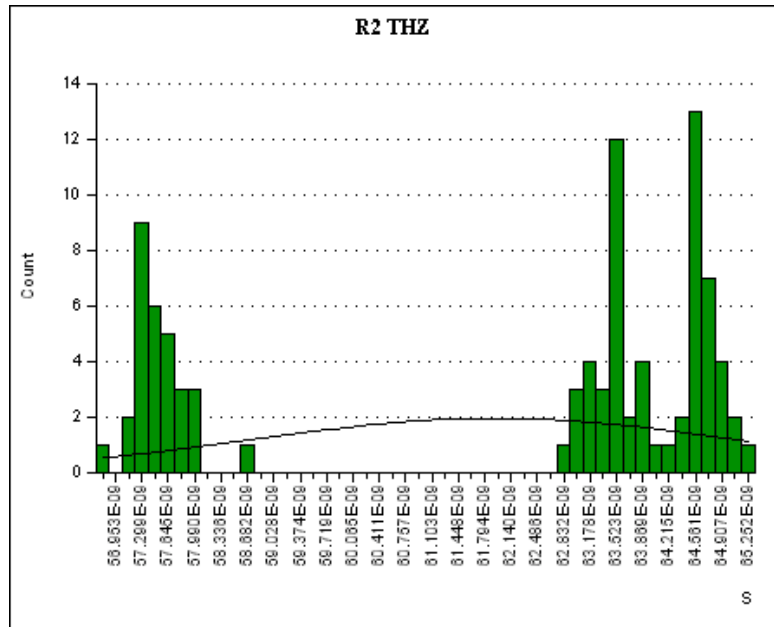
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.011, Test.Name=R2 THZ



Statistics: (S)

Max	65.252E-09	25%	57.617E-09	SpecHigh	N/A
Mean	61.881E-09	10%	57.291E-09	SpecLow	N/A
Min	56.780E-09	N	90	PctWithinSpec	N/A
Range	8.472E-09	Cp	N/A	PctDefSpec	N/A
StdDev	3.158E-09	Cpl	N/A	NWithinSpec	N/A
W	0.7504	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	64.788E-09	Skew	-0.6363		
75%	64.509E-09	Kurtosis	-1.4810		
Median	63.472E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

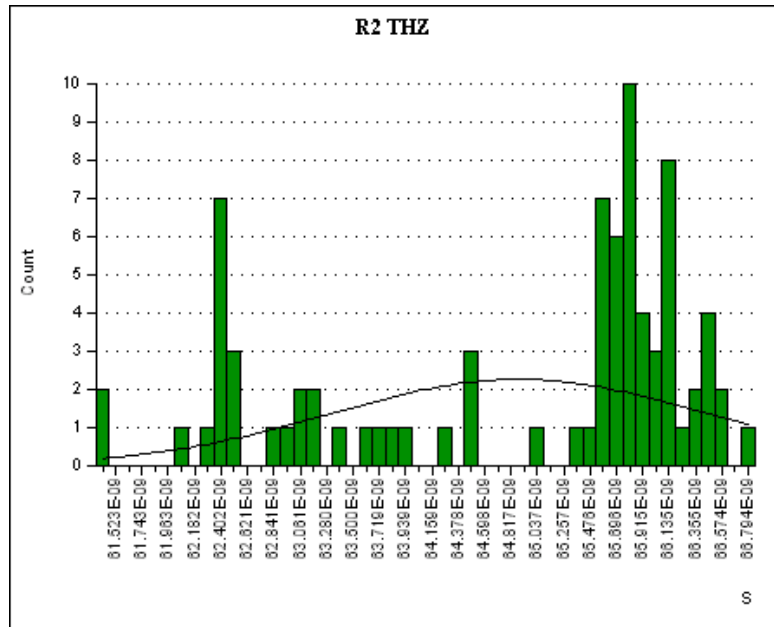
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=14.011, Test.Name=R2 THZ



Statistics: (S)

Max	66.794E-09	25%	63.301E-09	SpecHigh	N/A
Mean	64.853E-09	10%	62.358E-09	SpecLow	N/A
Min	61.414E-09	N	80	PctWithinSpec	N/A
Range	5.380E-09	Cp	N/A	c	
StdDev	1.546E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8375	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	66.322E-09	Skew	-0.7831		
75%	66.039E-09	Kurtosis	-0.9156		
Median	65.661E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

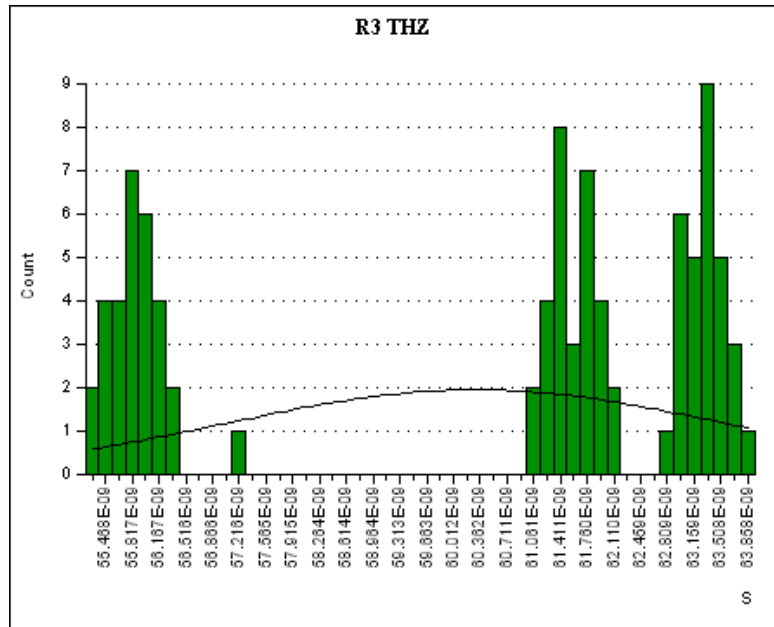
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.012, Test.Name=R3 THZ



Statistics: (S)

Max	63.858E-09	25%	56.036E-09	SpecHigh	N/A
Mean	60.252E-09	10%	55.665E-09	SpecLow	N/A
Min	55.293E-09	N	90	PctWithinSpec	N/A
Range	8.565E-09	Cp	N/A	PctDefSpec	N/A
StdDev	3.209E-09	Cpl	N/A	NWithinSpec	N/A
W	0.7845	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	63.439E-09	Skew	-0.5631		
75%	63.114E-09	Kurtosis	-1.4773		
Median	61.567E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

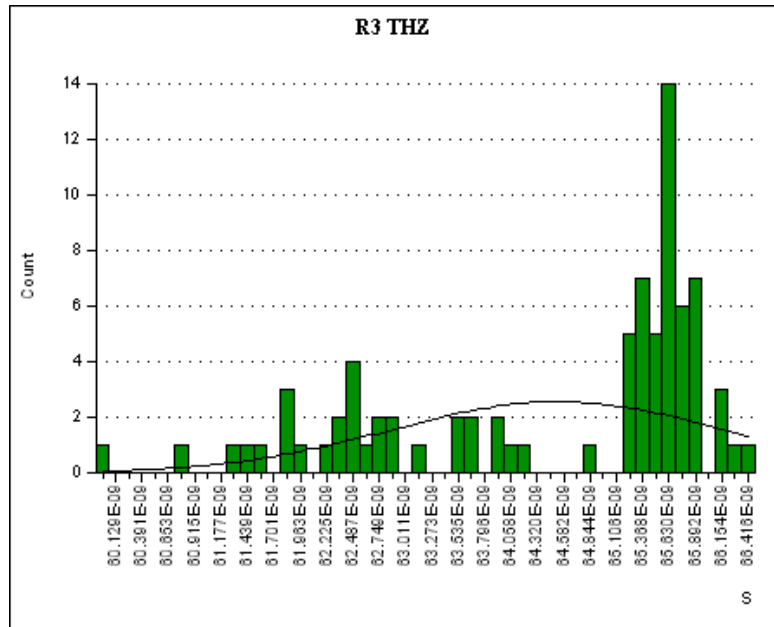
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=14.012, Test.Name=R3 THZ



Statistics: (S)

Max	66.416E-09	25%	62.829E-09	SpecHigh	N/A
Mean	64.481E-09	10%	61.886E-09	SpecLow	N/A
Min	59.998E-09	N	80	PctWithinSpec	N/A
Range	6.419E-09	Cp	N/A	c	
StdDev	1.630E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8296	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	65.850E-09	Skew	-0.8932		
75%	65.661E-09	Kurtosis	-0.5408		
Median	65.378E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

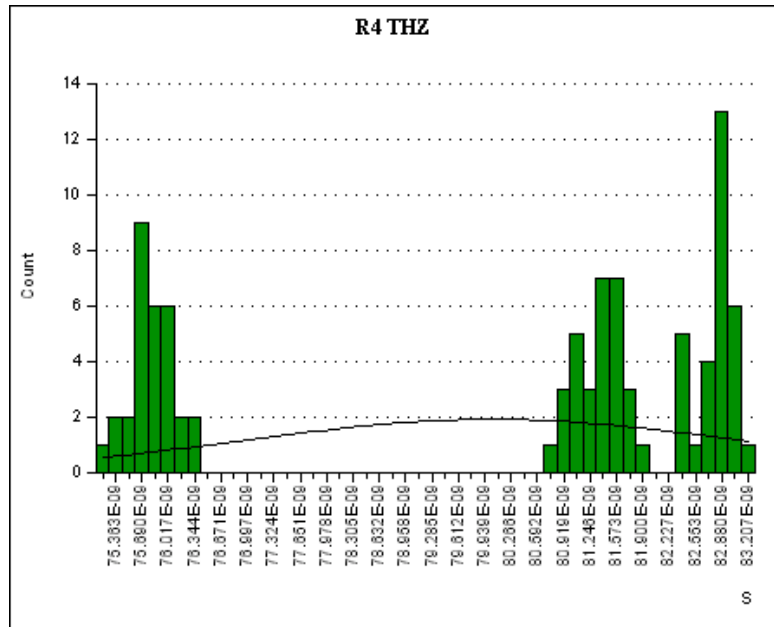
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.013, Test.Name=R4 THZ



Statistics: (S)

Max	83.207E-09	25%	76.036E-09	SpecHigh	N/A
Mean	79.992E-09	10%	75.665E-09	SpecLow	N/A
Min	75.200E-09	N	90	PctWithinSpec	N/A
Range	8.007E-09	Cp	N/A	PctDefSpec	N/A
StdDev	3.043E-09	Cpl	N/A	NWithinSpec	N/A
W	0.7690	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	82.928E-09	Skew	-0.5856		
75%	82.649E-09	Kurtosis	-1.4926		
Median	81.334E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

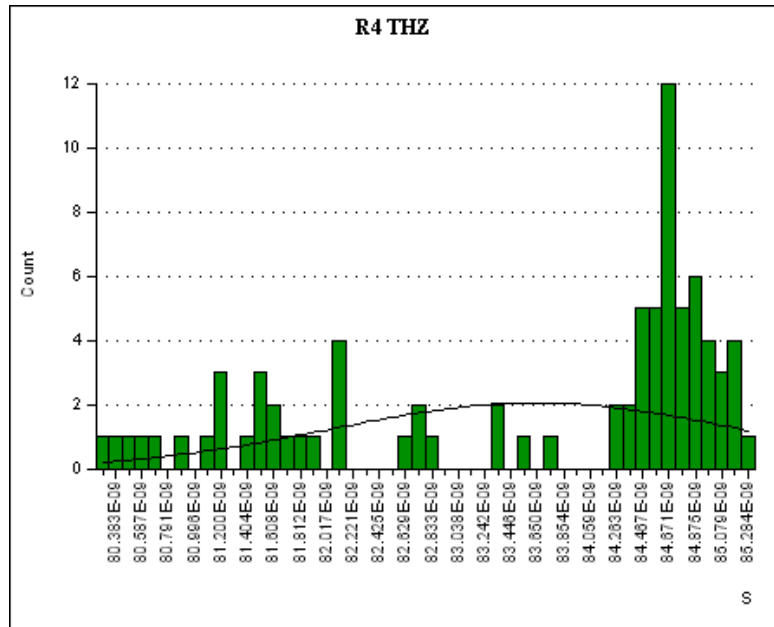
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=14.013, Test.Name=R4 THZ



Statistics: (S)

Max	85.284E-09	25%	82.122E-09	SpecHigh	N/A
Mean	83.608E-09	10%	81.225E-09	SpecLow	N/A
Min	80.281E-09	N	80	PctWithinSpec	N/A
Range	5.003E-09	Cp	N/A	PctDefSpec	N/A
StdDev	1.572E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8201	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	85.048E-09	Skew	-0.7865		
75%	84.812E-09	Kurtosis	-0.9657		
Median	84.481E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

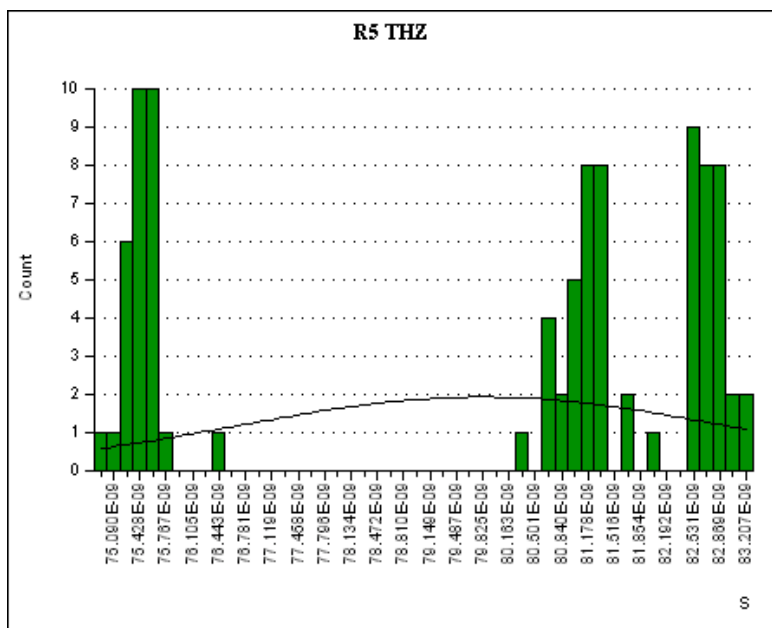
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.014, Test.Name=R5 THZ



Statistics: (S)

Max	83.207E-09	25%	75.572E-09	SpecHigh	N/A
Mean	79.771E-09	10%	75.386E-09	SpecLow	N/A
Min	74.921E-09	N	90	PctWithinSpec	N/A
Range	8.286E-09	Cp	N/A	PctDefSpec	N/A
StdDev	3.139E-09	Cpl	N/A	NWithinSpec	N/A
W	0.7694	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	82.835E-09	Skew	-0.5702		
75%	82.556E-09	Kurtosis	-1.4999		
Median	81.148E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

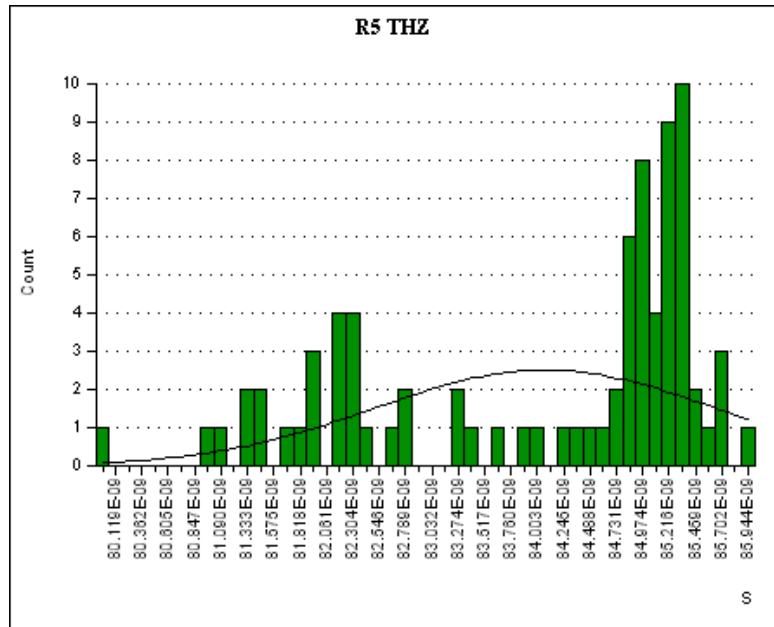
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=14.014, Test.Name=R5 THZ



Statistics: (S)

Max	85.944E-09	25%	82.405E-09	SpecHigh	N/A
Mean	84.037E-09	10%	81.744E-09	SpecLow	N/A
Min	79.998E-09	N	80	PctWithinSpec	N/A
Range	5.947E-09	Cp	N/A	c	
StdDev	1.540E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8413	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	85.378E-09	Skew	-0.8107		
75%	85.189E-09	Kurtosis	-0.7660		
Median	84.906E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

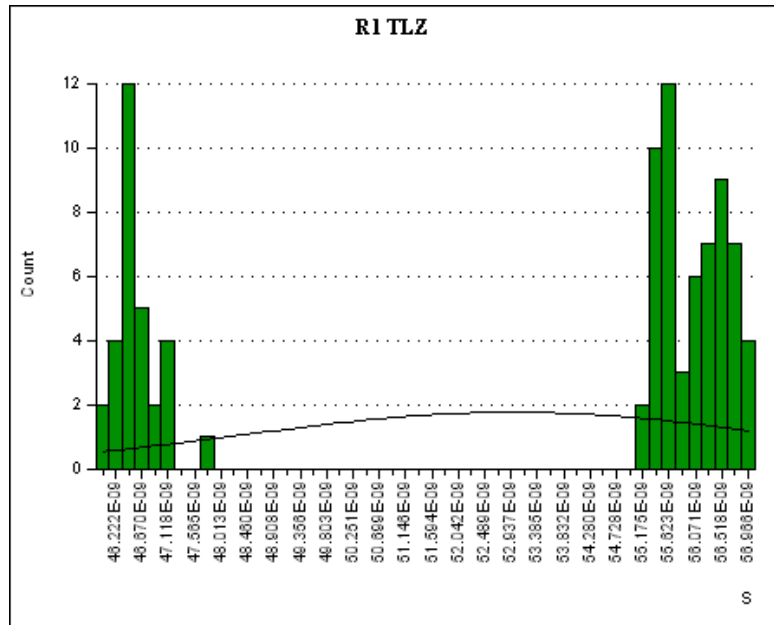
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.015, Test.Name=R1 TLZ



Statistics: (S)

Max	56.966E-09	25%	46.742E-09	SpecHigh	N/A
Mean	52.901E-09	10%	46.370E-09	SpecLow	N/A
Min	45.998E-09	N	90	PctWithinSpec	N/A
Range	10.968E-09	Cp	N/A	PctDefSpec	N/A
StdDev	4.517E-09	Cpl	N/A	NWithinSpec	N/A
W	0.6884	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	56.687E-09	Skew	-0.6987		
75%	56.315E-09	Kurtosis	-1.4948		
Median	55.583E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

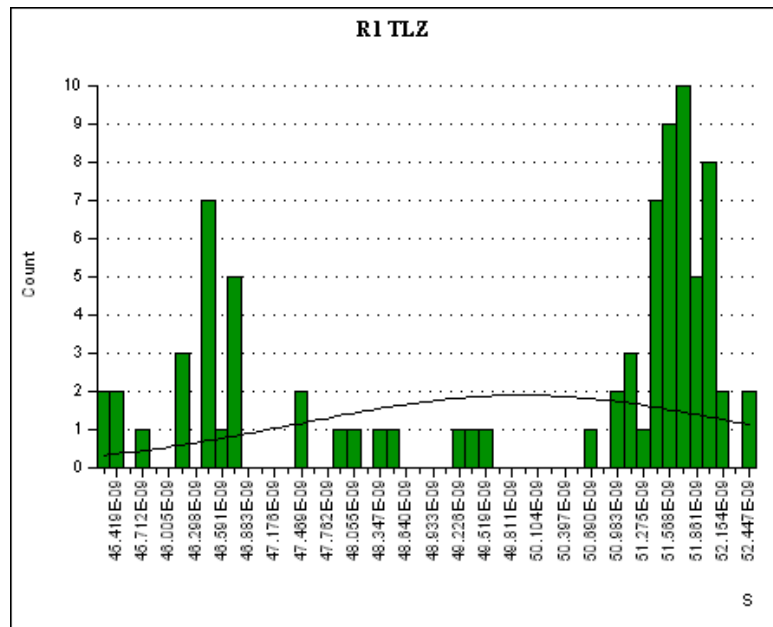
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=14.015, Test.Name=R1 TLZ



Statistics: (S)

Max	52.447E-09	25%	46.689E-09	SpecHigh	N/A
Mean	49.871E-09	10%	46.311E-09	SpecLow	N/A
Min	45.273E-09	N	80	PctWithinSpec	N/A
Range	7.174E-09	Cp	N/A	c	
StdDev	2.456E-09	Cpl	N/A	PctDefSpec	N/A
W	0.7796	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	51.975E-09	Skew	-0.7076		
75%	51.786E-09	Kurtosis	-1.2698		
Median	51.408E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

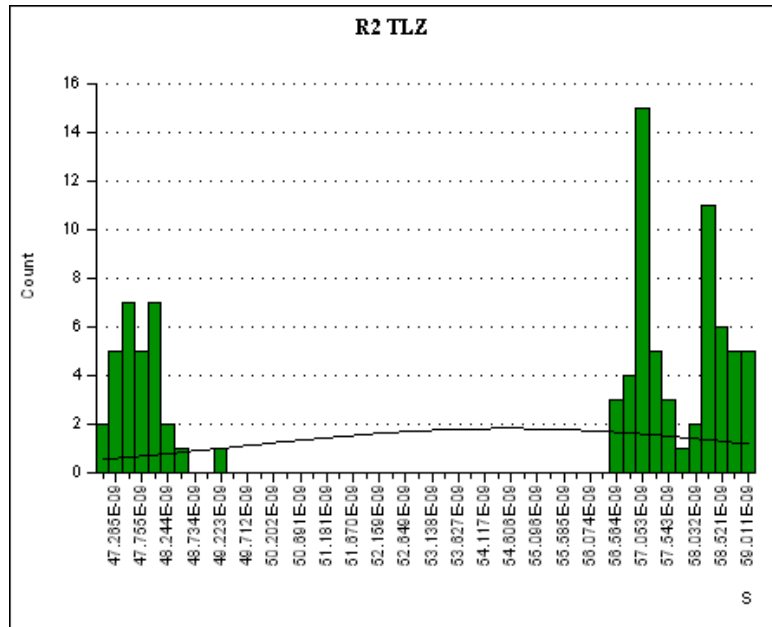
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.016, Test.Name=R2 TLZ



Statistics: (S)

Max	59.011E-09	25%	47.950E-09	SpecHigh	N/A
Mean	54.440E-09	10%	47.439E-09	SpecLow	N/A
Min	47.021E-09	N	90	PctWithinSpec	N/A
Range	11.990E-09	Cp	N/A	PctDefSpec	N/A
StdDev	4.813E-09	Cpl	N/A	NWithinSpec	N/A
W	0.7173	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	58.732E-09	Skew	-0.6739		
75%	58.267E-09	Kurtosis	-1.4889		
Median	57.071E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

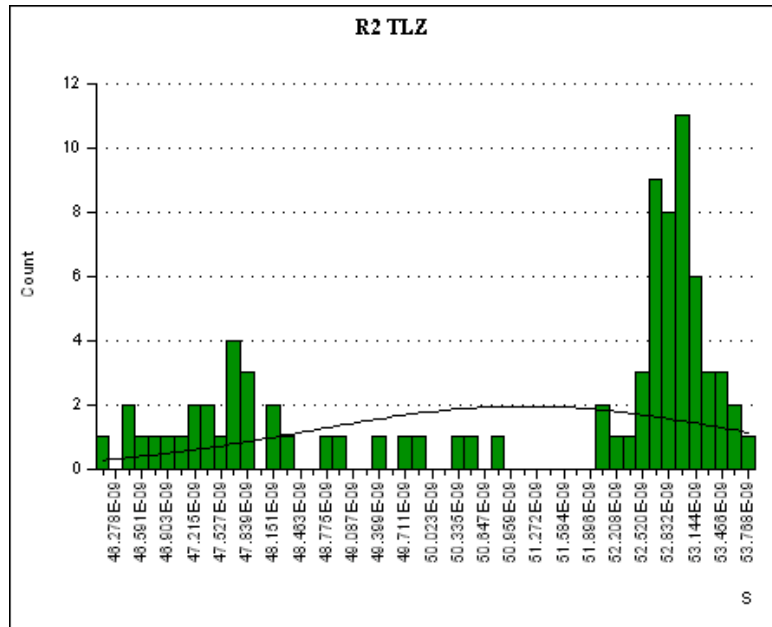
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=14.016, Test.Name=R2 TLZ



Statistics: (S)

Max	53.768E-09	25%	48.105E-09	SpecHigh	N/A
Mean	51.071E-09	10%	47.208E-09	SpecLow	N/A
Min	46.122E-09	N	80	PctWithinSpec	N/A
Range	7.646E-09	Cp	N/A	c	
StdDev	2.527E-09	Cpl	N/A	PctDefSpec	N/A
W	0.7876	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	53.296E-09	Skew	-0.7184		
75%	52.919E-09	Kurtosis	-1.2350		
Median	52.635E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

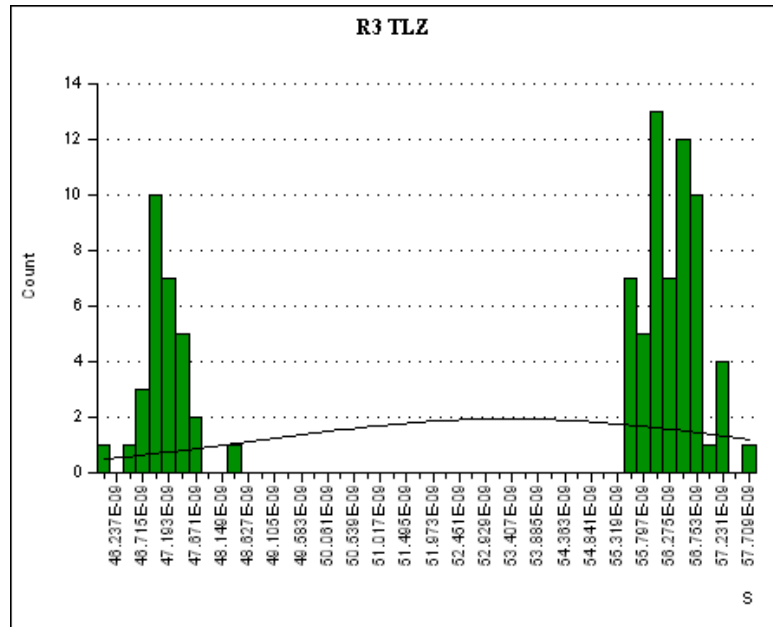
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.017, Test.Name=R3 TLZ



Statistics: (S)

Max	57.709E-09	25%	47.393E-09	SpecHigh	N/A
Mean	53.263E-09	10%	46.928E-09	SpecLow	N/A
Min	45.998E-09	N	90	PctWithinSpec	N/A
Range	11.711E-09	Cp	N/A	PctDefSpec	N/A
StdDev	4.402E-09	Cpl	N/A	NWithinSpec	N/A
W	0.6922	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	56.873E-09	Skew	-0.7025		
75%	56.513E-09	Kurtosis	-1.4869		
Median	55.955E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

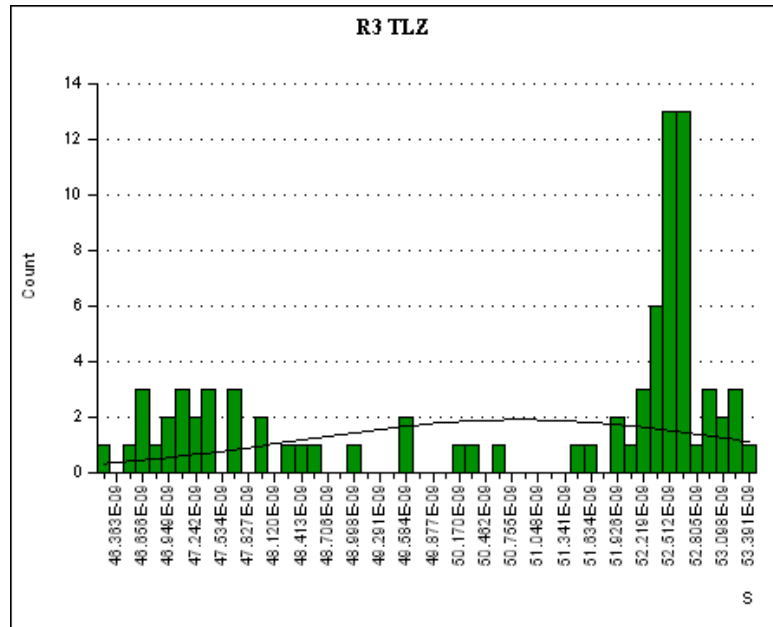
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=14.017, Test.Name=R3 TLZ



Statistics: (S)

Max	53.391E-09	25%	47.963E-09	SpecHigh	N/A
Mean	50.791E-09	10%	47.019E-09	SpecLow	N/A
Min	46.217E-09	N	80	PctWithinSpec	N/A
Range	7.174E-09	Cp	N/A	c	
StdDev	2.444E-09	Cpl	N/A	PctDefSpec	N/A
W	0.7818	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	52.919E-09	Skew	-0.7045		
75%	52.683E-09	Kurtosis	-1.2820		
Median	52.352E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

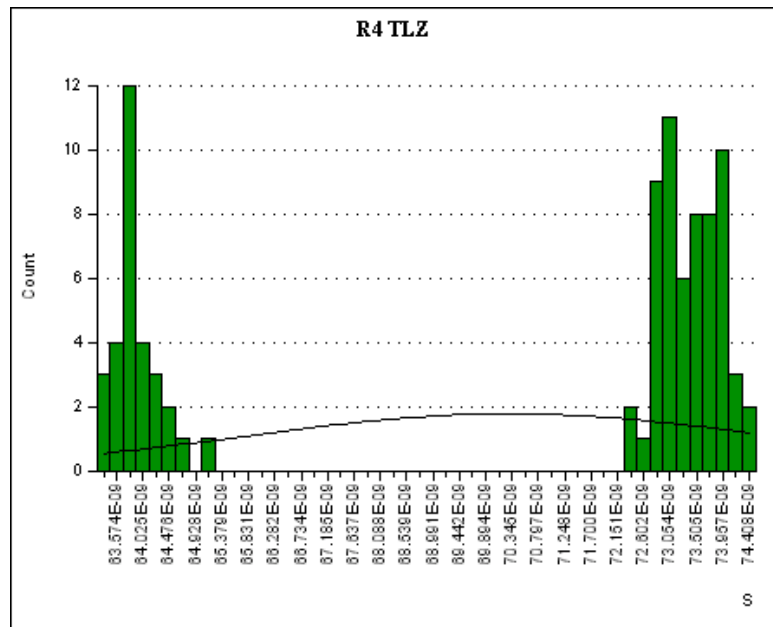
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.018, Test.Name=R4 TLZ



Statistics: (S)

Max	74.408E-09	25%	64.091E-09	SpecHigh	N/A
Mean	70.246E-09	10%	63.766E-09	SpecLow	N/A
Min	63.348E-09	N	90	PctWithinSpec	N/A
Range	11.060E-09	Cp	N/A	PctDefSpec	N/A
StdDev	4.518E-09	Cpl	N/A	NWithinSpec	N/A
W	0.6834	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	73.944E-09	Skew	-0.7021		
75%	73.665E-09	Kurtosis	-1.4961		
Median	73.025E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

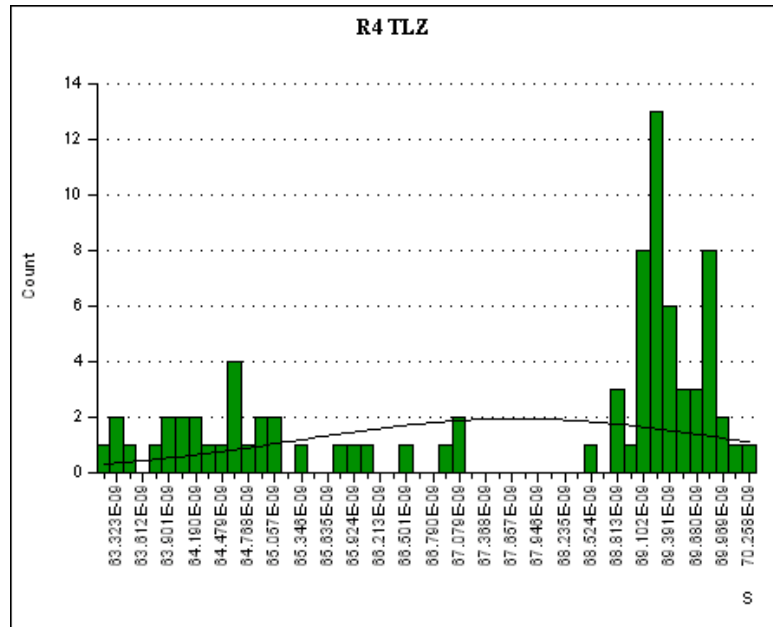
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=14.018, Test.Name=R4 TLZ



Statistics: (S)

Max	70.258E-09	25%	65.019E-09	SpecHigh	N/A
Mean	67.680E-09	10%	64.028E-09	SpecLow	N/A
Min	63.179E-09	N	80	PctWithinSpec	N/A
Range	7.079E-09	Cp	N/A	c	
StdDev	2.360E-09	Cpl	N/A	PctDefSpec	N/A
W	0.7956	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	69.833E-09	Skew	-0.6979		
75%	69.408E-09	Kurtosis	-1.2516		
Median	69.125E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

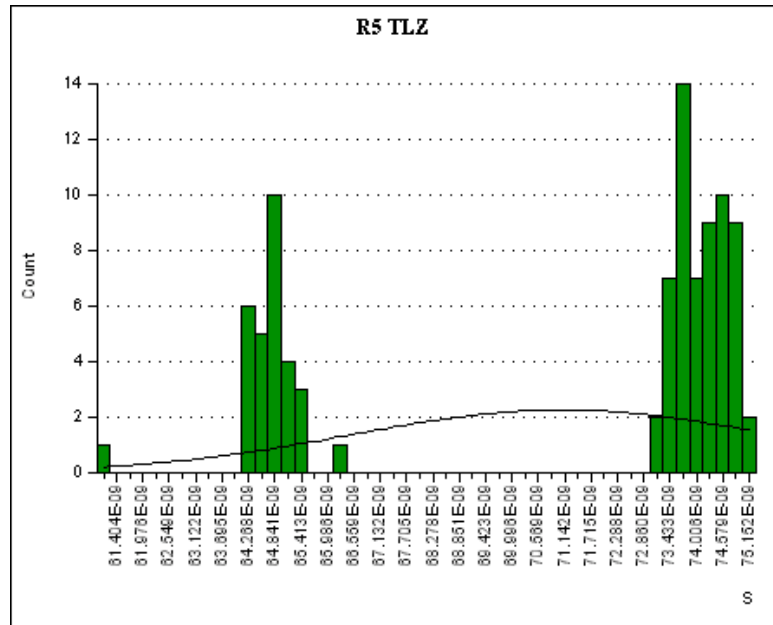
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.019, Test.Name=R5 TLZ



Statistics: (S)

Max	75.152E-09	25%	65.021E-09	SpecHigh	N/A
Mean	71.010E-09	10%	64.510E-09	SpecLow	N/A
Min	61.117E-09	N	90	PctWithinSpec	N/A
Range	14.035E-09	Cp	N/A	PctDefSpec	N/A
StdDev	4.528E-09	Cpl	N/A	NWithinSpec	N/A
W	0.7114	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	74.873E-09	Skew	-0.7242		
75%	74.408E-09	Kurtosis	-1.3876		
Median	73.676E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

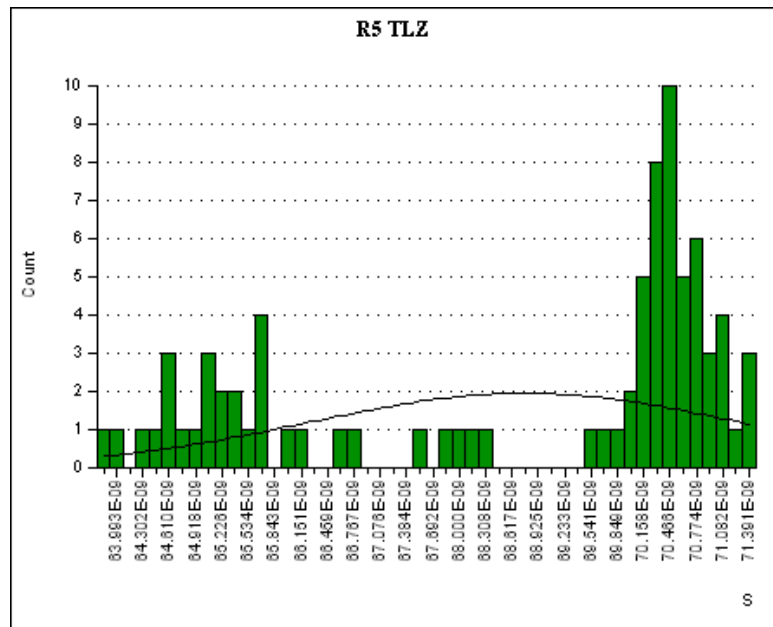
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=14.019, Test.Name=R5 TLZ



Statistics: (S)

Max	71.391E-09	25%	65.680E-09	SpecHigh	N/A
Mean	68.719E-09	10%	64.878E-09	SpecLow	N/A
Min	63.839E-09	N	80	PctWithinSpec	N/A
Range	7.551E-09	Cp	N/A	c	
StdDev	2.517E-09	Cpl	N/A	PctDefSpec	N/A
W	0.7934	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	70.966E-09	Skew	-0.7099		
75%	70.635E-09	Kurtosis	-1.2407		
Median	70.211E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

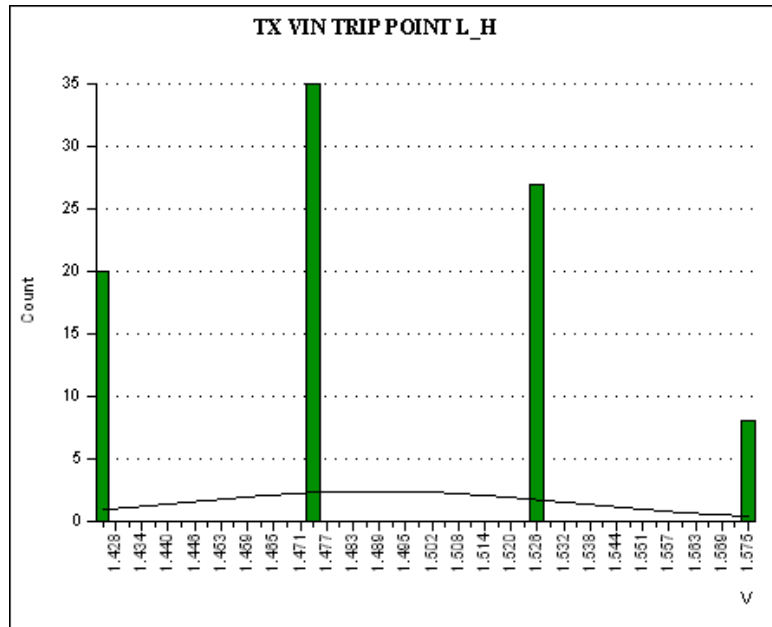
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.000, Test.Name=TX VIN TRIP POINT L_H



Statistics: (V)

Max	1.575	25%	1.475	SpecHigh	N/A
Mean	1.488	10%	1.425	SpecLow	N/A
Min	1.425	N	90	PctWithinSpec	N/A
Range	150.001E-03	Cp	N/A	c	
StdDev	45.321E-03	Cpl	N/A	PctDefSpec	N/A
W	0.8727	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	1.525	Skew	0.2073		
75%	1.525	Kurtosis	-0.7494		
Median	1.475				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

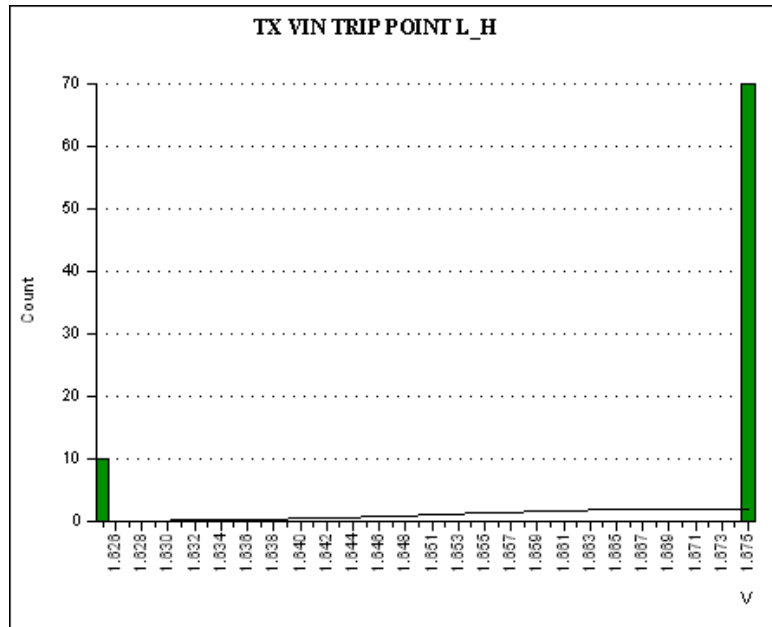
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=15.000, Test.Name=TX VIN TRIP POINT L_H



Statistics: (V)

Max	1.675	25%	1.675	SpecHigh	N/A
Mean	1.669	10%	1.625	SpecLow	N/A
Min	1.625	N	80	PctWithinSpec	N/A
Range	50.000E-03	Cp	N/A	PctDefSpec	N/A
StdDev	16.640E-03	Cpl	N/A	NWithinSpec	N/A
W	0.3877	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.675	Skew	-2.3114		
75%	1.675	Kurtosis	3.4274		
Median	1.675				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

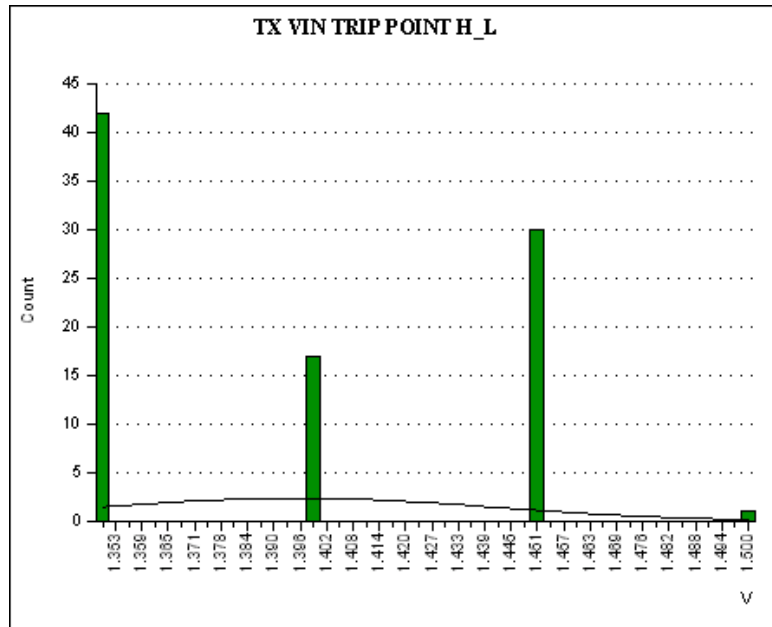
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.001, Test.Name=TX VIN TRIP POINT H_L



Statistics: (V)

Max	1.500	25%	1.350	SpecHigh	N/A
Mean	1.394	10%	1.350	SpecLow	N/A
Min	1.350	N	90	PctWithinSpec	N/A
Range	150.001E-03	Cp	N/A	c	
StdDev	45.865E-03	Cpl	N/A	PctDefSpec	N/A
W	0.7606	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	1.450	Skew	0.3139		
75%	1.450	Kurtosis	-1.5453		
Median	1.400				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C:	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

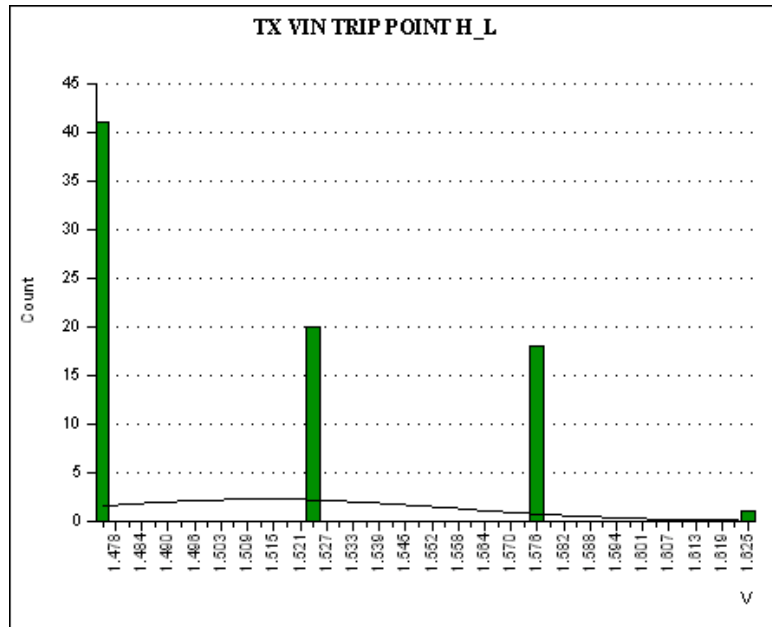
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=15.001, Test.Name=TX VIN TRIP POINT H_L



Statistics: (V)

Max	1.625	25%	1.475	SpecHigh	N/A
Mean	1.512	10%	1.475	SpecLow	N/A
Min	1.475	N	80	PctWithinSpec	N/A
Range	150.001E-03	Cp	N/A	c	
StdDev	42.653E-03	Cpl	N/A	PctDefSpec	N/A
W	0.7638	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	1.575	Skew	0.6634		
75%	1.525	Kurtosis	-0.9469		
Median	1.475				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

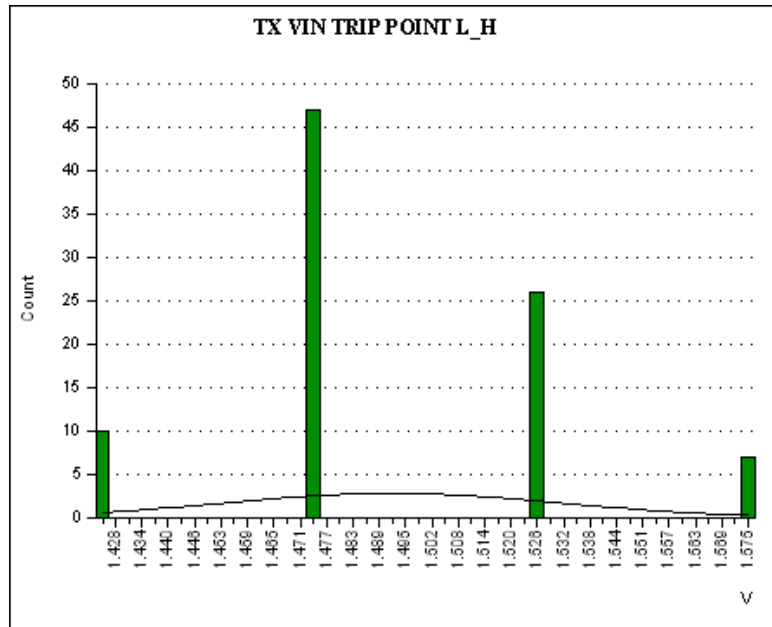
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.002, Test.Name=TX VIN TRIP POINT L_H



Statistics: (V)

Max	1.575	25%	1.475	SpecHigh	N/A
Mean	1.492	10%	1.425	SpecLow	N/A
Min	1.425	N	90	PctWithinSpec	N/A
Range	150.001E-03	Cp	N/A	PctDefSpec	N/A
StdDev	38.947E-03	Cpl	N/A	NWithinSpec	N/A
W	0.8438	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.525	Skew	0.3566		
75%	1.525	Kurtosis	-0.1218		
Median	1.475				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

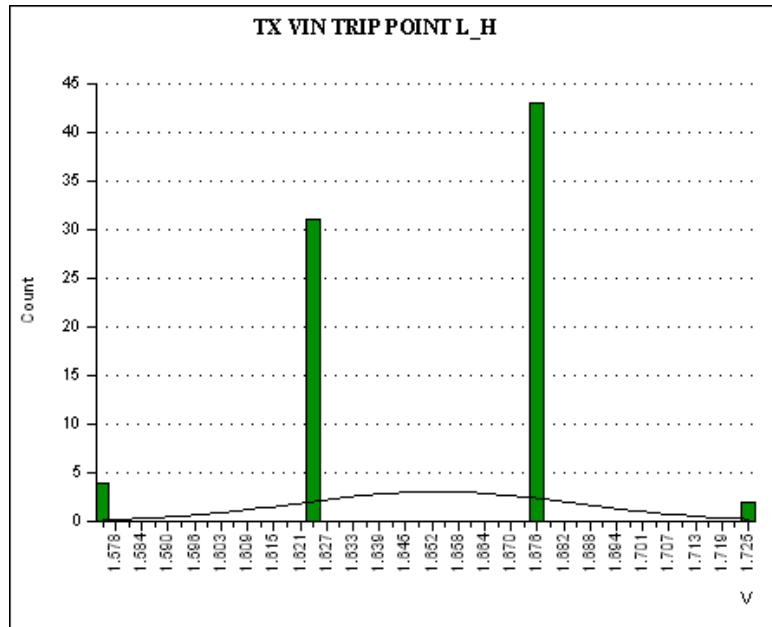
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=15.002, Test.Name=TX VIN TRIP POINT L_H



Statistics: (V)

Max	1.725	25%	1.625	SpecHigh	N/A
Mean	1.652	10%	1.625	SpecLow	N/A
Min	1.575	N	80	PctWithinSpec	N/A
Range	150.000E-03	Cp	N/A	PctDefSpec	N/A
StdDev	31.766E-03	Cpl	N/A	NWithinSpec	N/A
W	0.7775	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.675	Skew	-0.4476		
75%	1.675	Kurtosis	-0.0949		
Median	1.675				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

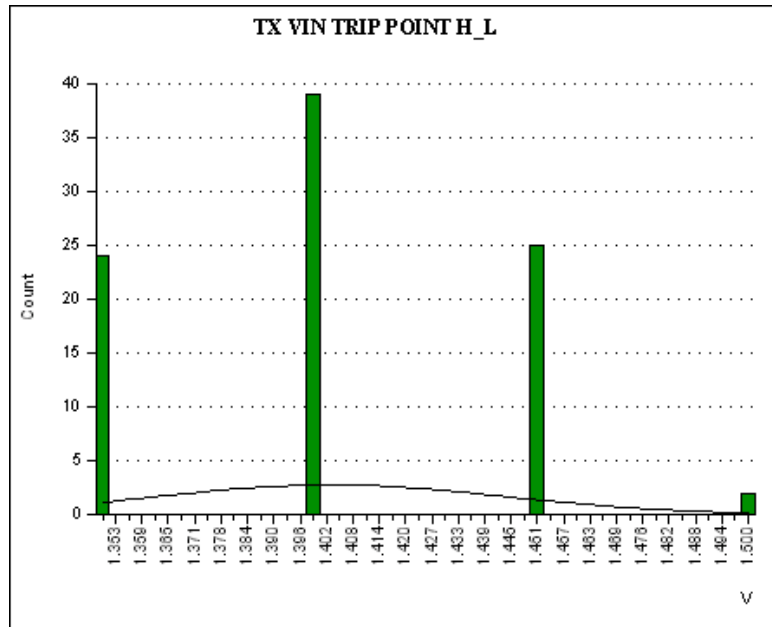
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.003, Test.Name=TX VIN TRIP POINT H_L



Statistics: (V)

Max	1.500	25%	1.350	SpecHigh	N/A
Mean	1.403	10%	1.350	SpecLow	N/A
Min	1.350	N	90	PctWithinSpec	N/A
Range	150.001E-03	Cp	N/A	PctDefSpec	N/A
StdDev	39.917E-03	Cpl	N/A	NWithinSpec	N/A
W	0.8450	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.450	Skew	0.1701		
75%	1.450	Kurtosis	-0.7876		
Median	1.400				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

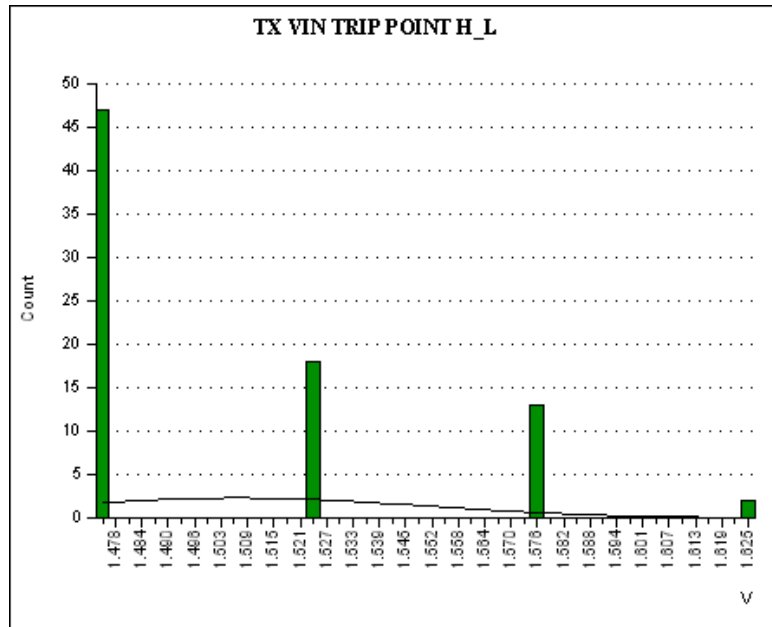
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=15.003, Test.Name=TX VIN TRIP POINT H_L



Statistics: (V)

Max	1.625	25%	1.475	SpecHigh	N/A
Mean	1.506	10%	1.475	SpecLow	N/A
Min	1.475	N	80	PctWithinSpec	N/A
Range	150.001E-03	Cp	N/A	PctDefSpec	N/A
StdDev	42.378E-03	Cpl	N/A	NWithinSpec	N/A
W	0.7259	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.575	Skew	1.0675		
75%	1.525	Kurtosis	-0.0042		
Median	1.475				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

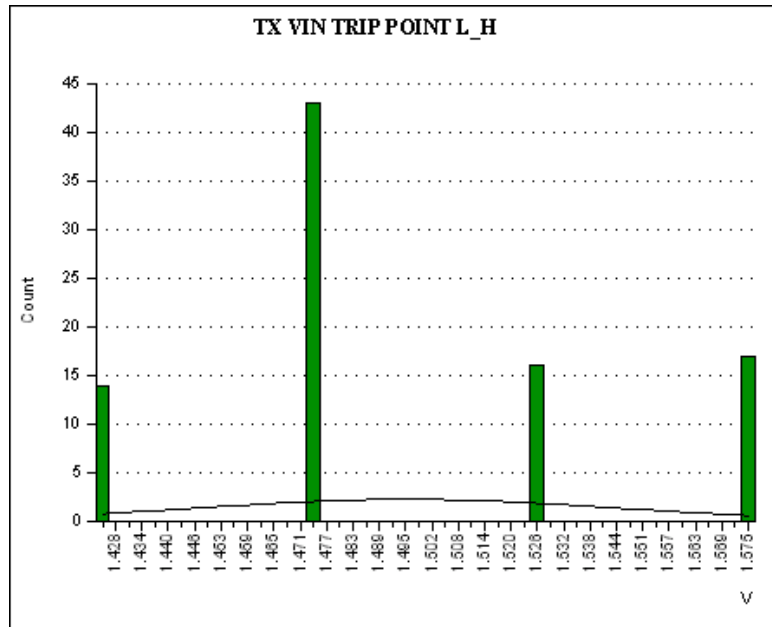
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.004, Test.Name=TX VIN TRIP POINT L_H



Statistics: (V)

Max	1.575	25%	1.475	SpecHigh	N/A
Mean	1.495	10%	1.425	SpecLow	N/A
Min	1.425	N	90	PctWithinSpec	N/A
Range	150.001E-03	Cp	N/A	PctDefSpec	N/A
StdDev	48.460E-03	Cpl	N/A	NWithinSpec	N/A
W	0.8443	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.575	Skew	0.4029		
75%	1.525	Kurtosis	-0.8102		
Median	1.475				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

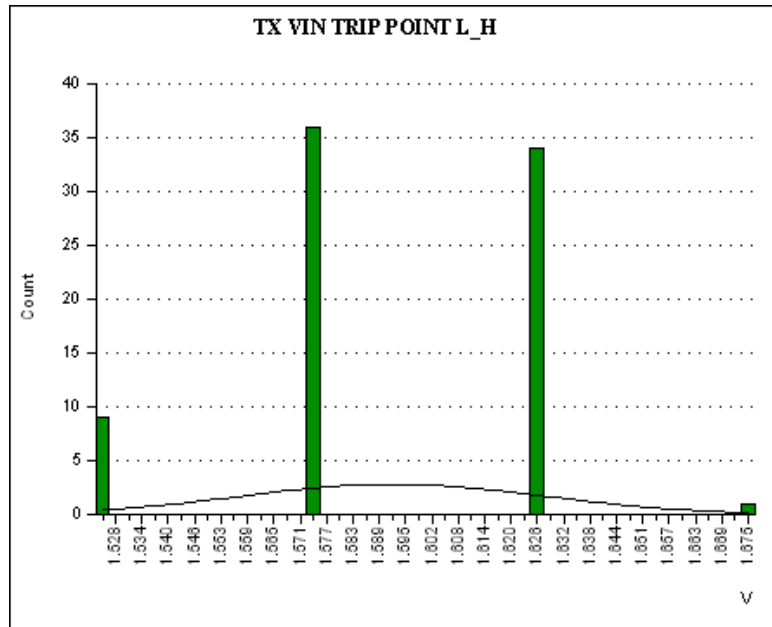
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=15.004, Test.Name=TX VIN TRIP POINT L_H



Statistics: (V)

Max	1.675	25%	1.575	SpecHigh	N/A
Mean	1.592	10%	1.525	SpecLow	N/A
Min	1.525	N	80	PctWithinSpec	N/A
Range	150.000E-03	Cp	N/A	c	
StdDev	34.626E-03	Cpl	N/A	PctDefSpec	N/A
W	0.8072	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	1.625	Skew	-0.3298		
75%	1.625	Kurtosis	-0.5369		
Median	1.575				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

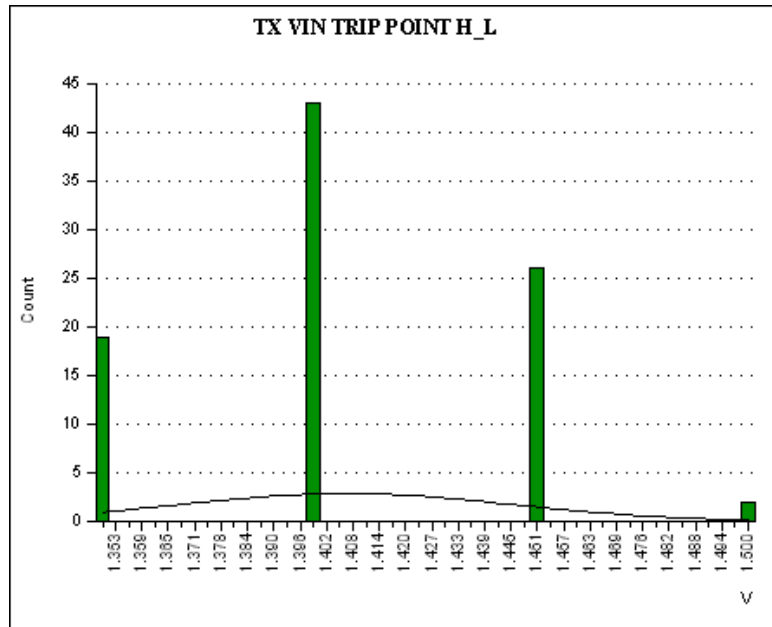
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.005, Test.Name=TX VIN TRIP POINT H_L



Statistics: (V)

Max	1.500	25%	1.400	SpecHigh	N/A
Mean	1.406	10%	1.350	SpecLow	N/A
Min	1.350	N	90	PctWithinSpec	N/A
Range	150.001E-03	Cp	N/A	PctDefSpec	N/A
StdDev	38.092E-03	Cpl	N/A	NWithinSpec	N/A
W	0.8438	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.450	Skew	0.1012		
75%	1.450	Kurtosis	-0.5903		
Median	1.400				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

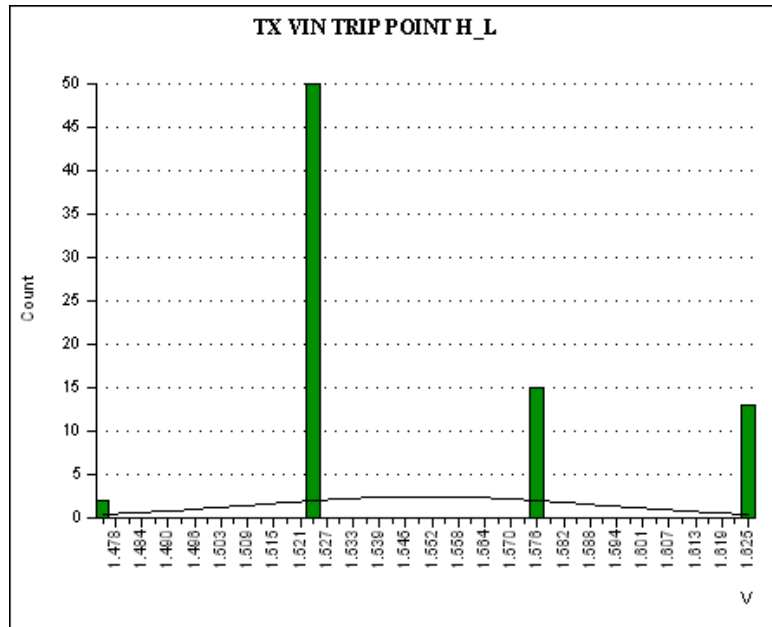
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=15.005, Test.Name=TX VIN TRIP POINT H_L



Statistics: (V)

Max	1.625	25%	1.525	SpecHigh	N/A
Mean	1.549	10%	1.525	SpecLow	N/A
Min	1.475	N	80	PctWithinSpec	N/A
Range	150.001E-03	Cp	N/A	PctDefSpec	N/A
StdDev	39.773E-03	Cpl	N/A	NWithinSpec	N/A
W	0.7299	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.625	Skew	0.8931		
75%	1.575	Kurtosis	-0.3311		
Median	1.525				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

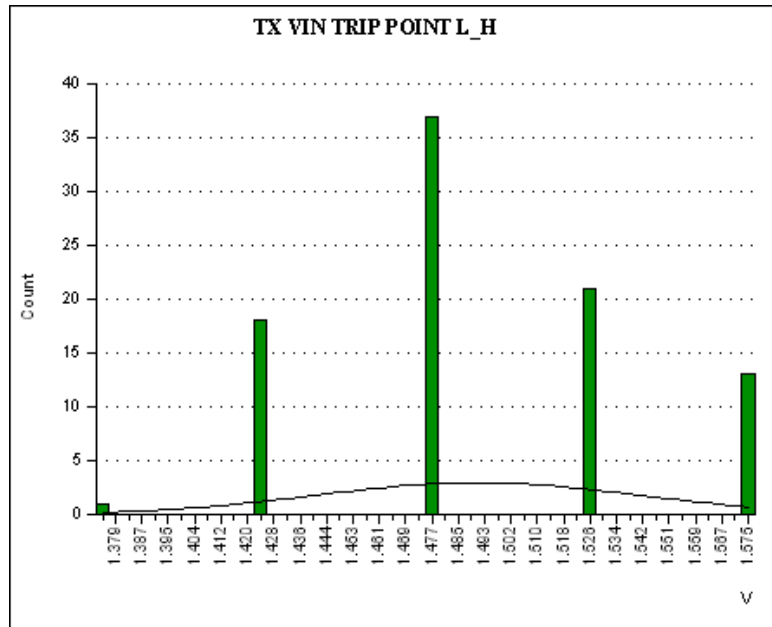
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.006, Test.Name=TX VIN TRIP POINT L_H



Statistics: (V)

Max	1.575	25%	1.475	SpecHigh	N/A
Mean	1.490	10%	1.425	SpecLow	N/A
Min	1.375	N	90	PctWithinSpec	N/A
Range	200.001E-03	Cp	N/A	PctDefSpec	N/A
StdDev	49.407E-03	Cpl	N/A	NWithinSpec	N/A
W	0.8886	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.575	Skew	0.2187		
75%	1.525	Kurtosis	-0.6666		
Median	1.475				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

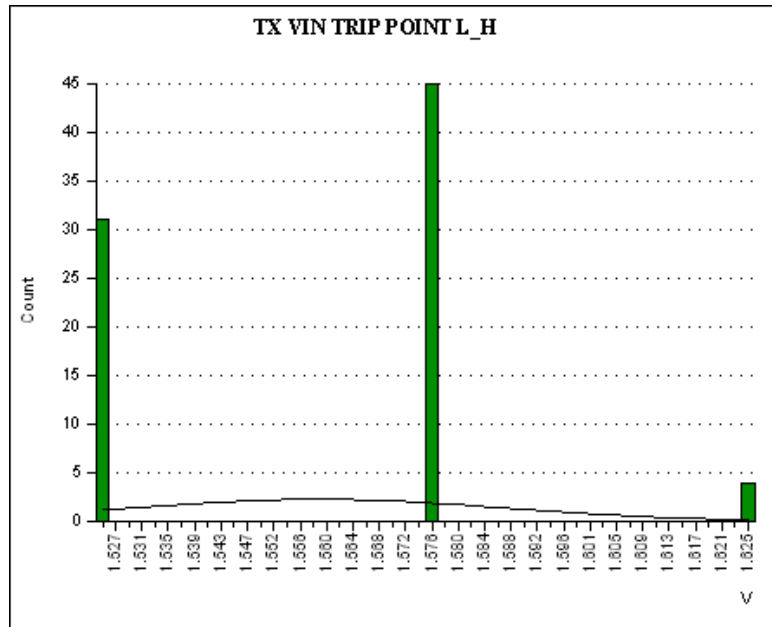
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=15.006, Test.Name=TX VIN TRIP POINT L_H



Statistics: (V)

Max	1.625	25%	1.525	SpecHigh	N/A
Mean	1.558	10%	1.525	SpecLow	N/A
Min	1.525	N	80	PctWithinSpec	N/A
Range	99.999E-03	Cp	N/A	c	
StdDev	28.622E-03	Cpl	N/A	PctDefSpec	N/A
W	0.7312	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	1.575	Skew	0.1582		
75%	1.575	Kurtosis	-0.6556		
Median	1.575				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

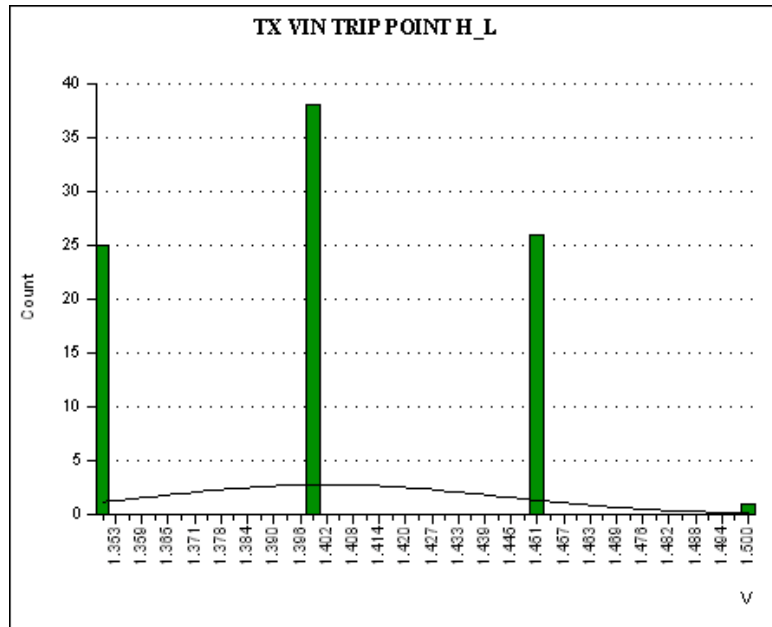
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.007, Test.Name=TX VIN TRIP POINT H_L



Statistics: (V)

Max	1.500	25%	1.350	SpecHigh	N/A
Mean	1.402	10%	1.350	SpecLow	N/A
Min	1.350	N	90	PctWithinSpec	N/A
Range	150.001E-03	Cp	N/A	c	
StdDev	39.270E-03	Cpl	N/A	PctDefSpec	N/A
W	0.8329	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	1.450	Skew	0.0832		
75%	1.450	Kurtosis	-1.0138		
Median	1.400				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C45C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Conditions

Temp	Vcc
-40C	4.5V
25C	
85C	

Data: Raw Data

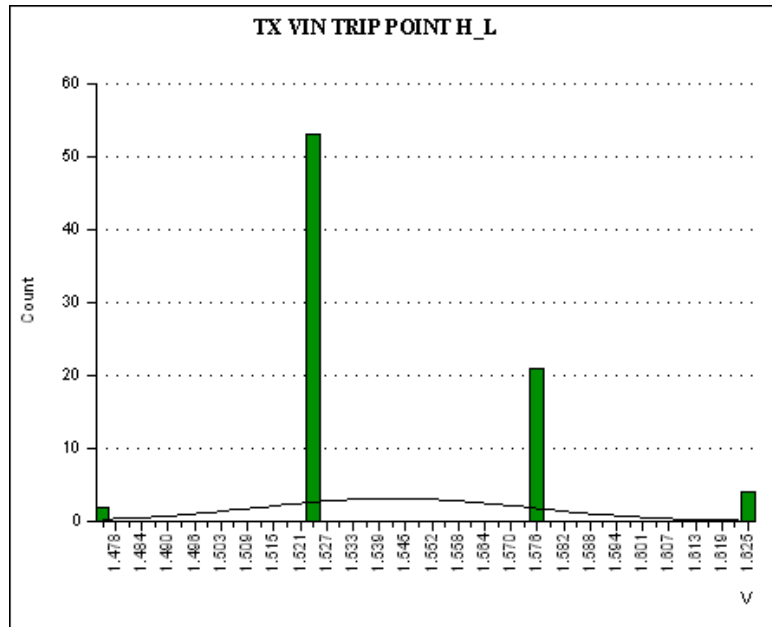
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=15.007, Test.Name=TX VIN TRIP POINT H_L



Statistics: (V)

Max	1.625	25%	1.525	SpecHigh	N/A
Mean	1.542	10%	1.525	SpecLow	N/A
Min	1.475	N	80	PctWithinSpec	N/A
Range	150.001E-03	Cp	N/A	PctDefSpec	N/A
StdDev	30.754E-03	Cpl	N/A	NWithinSpec	N/A
W	0.7145	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.575	Skew	0.9855		
75%	1.575	Kurtosis	0.8607		
Median	1.525				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2475C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH. AT	1	0
213L2475R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH. AT	-	0

Data: Raw Data

Stat limits applied

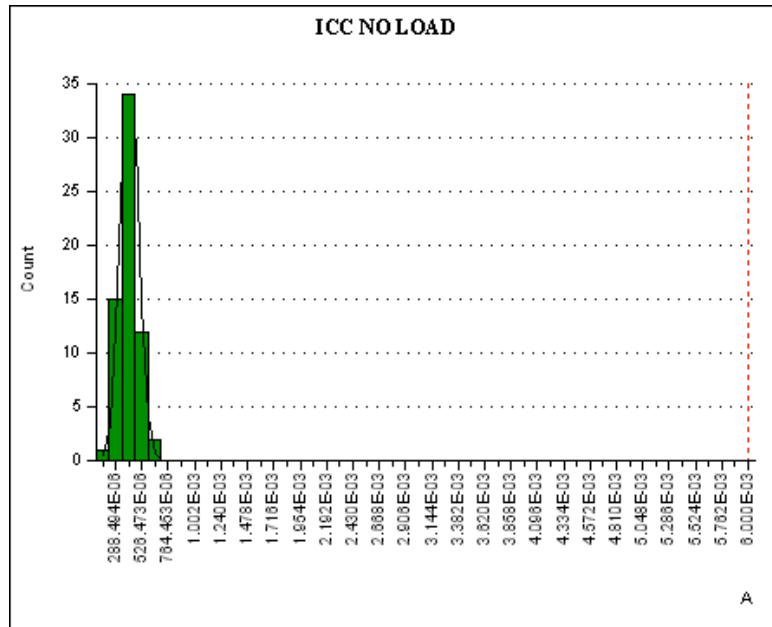
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=1.000, Test.Name=ICC NO LOAD



Statistics: (A)

Max	624.703E-06	25%	351.511E-06	SpecHigh	6.000E-03
Mean	406.655E-06	10%	308.834E-06	SpecLow	N/A
Min	169.504E-06	N	64	PctWithinSpec	100.00
Range	455.199E-06	Cp	N/A	PctDefSpec	0
StdDev	81.244E-06	Cpl	N/A	NWithinSpec	64
W	0.9782	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.3146	Cpk	>4.0000		
90%	495.343E-06	Skew	-0.1982		
75%	454.763E-06	Kurtosis	0.9362		
Median	419.094E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

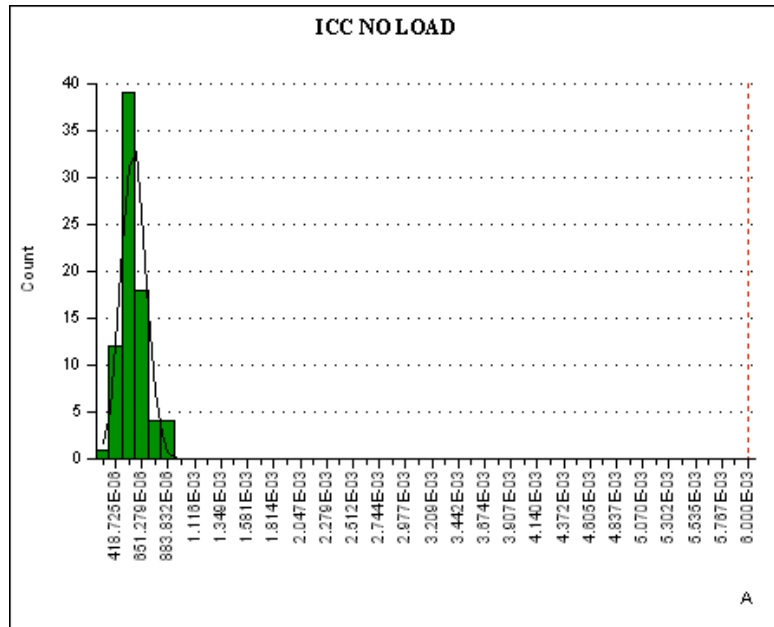
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=1.000, Test.Name=ICC NO LOAD



Statistics: (A)

Max	871.083E-06	25%	494.408E-06	SpecHigh	6.000E-03
Mean	568.493E-06	10%	444.686E-06	SpecLow	N/A
Min	302.449E-06	N	78	PctWithinSpec	100.00
Range	568.634E-06	Cp	N/A	PctDefSpec	0
StdDev	108.454E-06	Cpl	N/A	NWithinSpec	78
W	0.9673	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0423	Cpk	>4.0000		
90%	731.481E-06	Skew	0.6137		
75%	625.202E-06	Kurtosis	0.7178		
Median	559.503E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

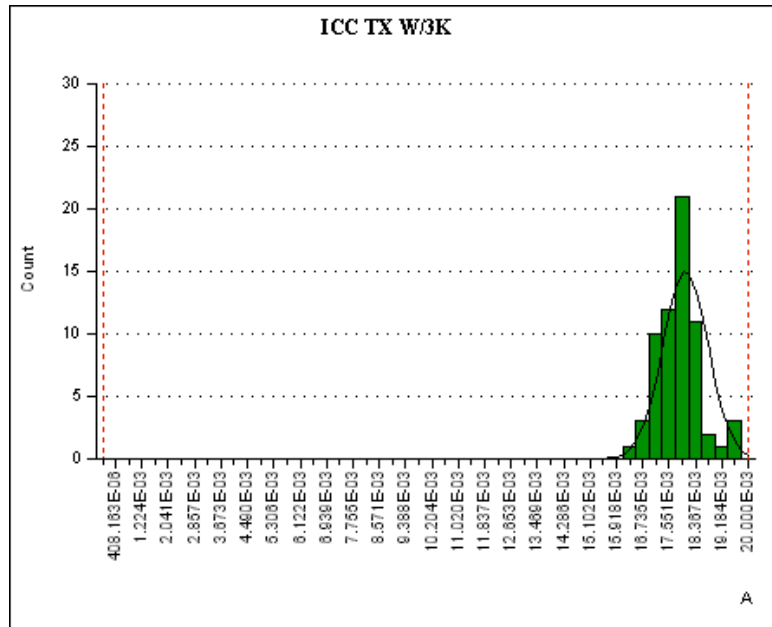
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=1.001, Test.Name=ICC TX W/3K



Statistics: (A)

Max	19.783E-03	25%	17.421E-03	SpecHigh	20.000E-03
Mean	17.863E-03	10%	17.069E-03	SpecLow	0
Min	16.457E-03	N	64	PctWithinSpec	100.00
Range	3.326E-03	Cp	>4.0000	PctDefSpec	0
StdDev	6.93218E-06	Cpl	>4.0000	NWithinSpec	64
W	0.9614	Cpu	1.0274	NOutsideSpec	0
WpValue	0.0432	Cpk	1.0274		
90%	18.555E-03	Skew	0.5802		
75%	18.195E-03	Kurtosis	0.9278		
Median	17.840E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

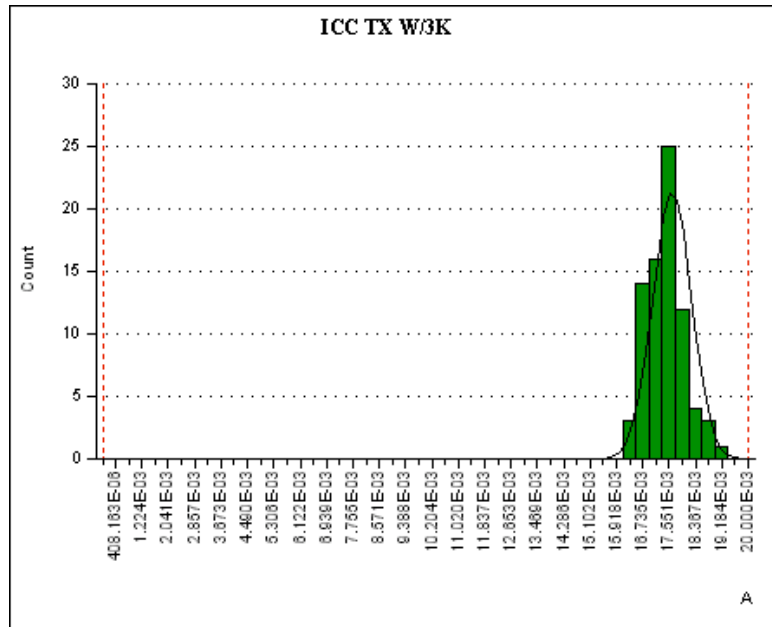
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=1.001, Test.Name=ICC TX W/3K



Statistics: (A)

Max	19.366E-03	25%	17.011E-03	SpecHigh	20.000E-03
Mean	17.456E-03	10%	16.647E-03	SpecLow	0
Min	16.374E-03	N	78	PctWithinSpec	100.00
Range	2.992E-03	Cp	>4.0000	c	
StdDev	596.691E-06	Cpl	>4.0000	PctDefSpec	0
W	0.9747	Cpu	1.4210	NWithinSpec	78
WpValue	0.1233	Cpk	1.4210	NOutsideSpec	0
90%	18.169E-03	Skew	0.5525		
75%	17.761E-03	Kurtosis	0.5305		
Median	17.456E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T		0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T		0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T		0

Data: Raw Data

Stat limits applied

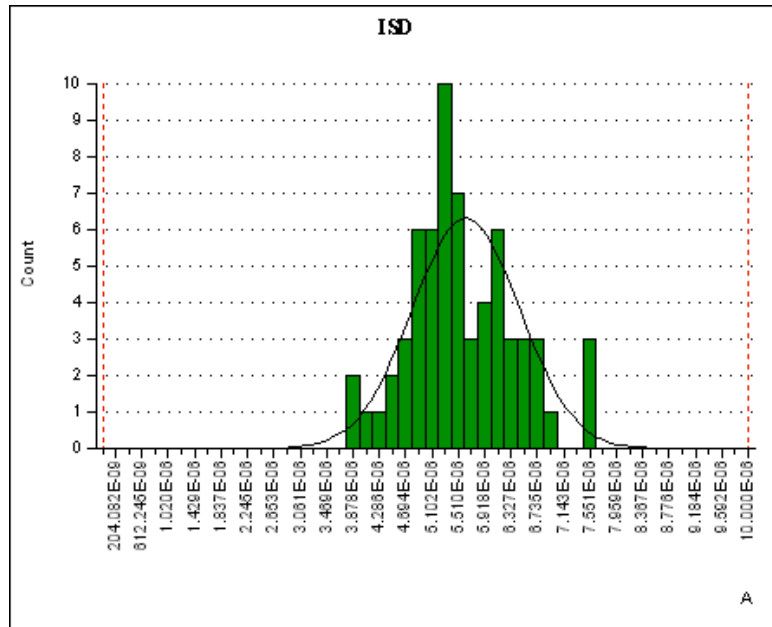
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=1.002, Test.Name=ISD



Statistics: (A)

Max	7.588E-06	25%	5.044E-06	SpecHigh	10.000E-06
Mean	5.565E-06	10%	4.601E-06	SpecLow	0
Min	3.809E-06	N	64	PctWithinSpec	100.00
Range	3.779E-06	Cp	2.0202	PctDefSpec	0
StdDev	825.007E-09	Cpl	2.2484	NWithinSpec	64
W	0.9791	Cpu	1.7920	NOutsideSpec	0
WpValue	0.3478	Cpk	1.7920		
90%	6.660E-06	Skew	0.3574		
75%	6.065E-06	Kurtosis	0.1878		
Median	5.427E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

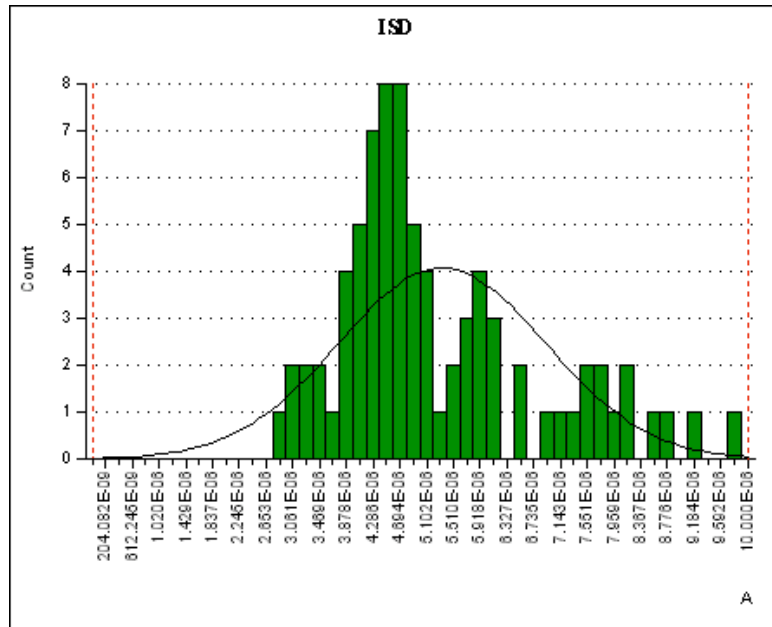
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=1.002, Test.Name=ISD



Statistics: (A)

Max	9.760E-06	25%	4.308E-06	SpecHigh	10.000E-06
Mean	5.274E-06	10%	3.635E-06	SpecLow	0
Min	2.821E-06	N	78	PctWithinSpec	100.00
Range	6.938E-06	Cp	1.0693	PctDefSpec	0
StdDev	1.559E-06	Cpl	1.1278	NWithinSpec	78
W	0.9185	Cpu	1.0108	NOutsideSpec	0
WpValue	0.0001	Cpk	1.0108		
90%	7.685E-06	Skew	0.9592		
75%	6.012E-06	Kurtosis	0.3797		
Median	4.775E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

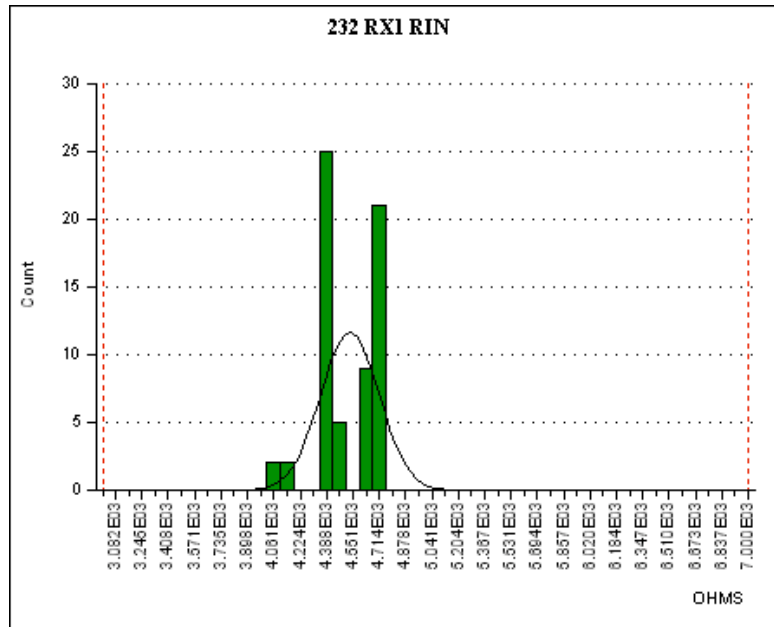
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=2.000, Test.Name=232 RX1 RIN



Statistics: (OHMS)

Max	4.752E03	25%	4.391E03	SpecHigh	7.000E03
Mean	4.514E03	10%	4.359E03	SpecLow	3.000E03
Min	4.082E03	N	64	PctWithinSpec	100.00
Range	670.330	Cp	3.7303	c	
StdDev	178.718	Cpl	2.8244	PctDefSpec	0
W	0.8702	Cpu	>4.0000	NWithinSpec	64
WpValue	0.0000	Cpk	2.8244	NOutsideSpec	0
90%	4.710E03	Skew	-0.4781		
75%	4.683E03	Kurtosis	-0.5009		
Median	4.449E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

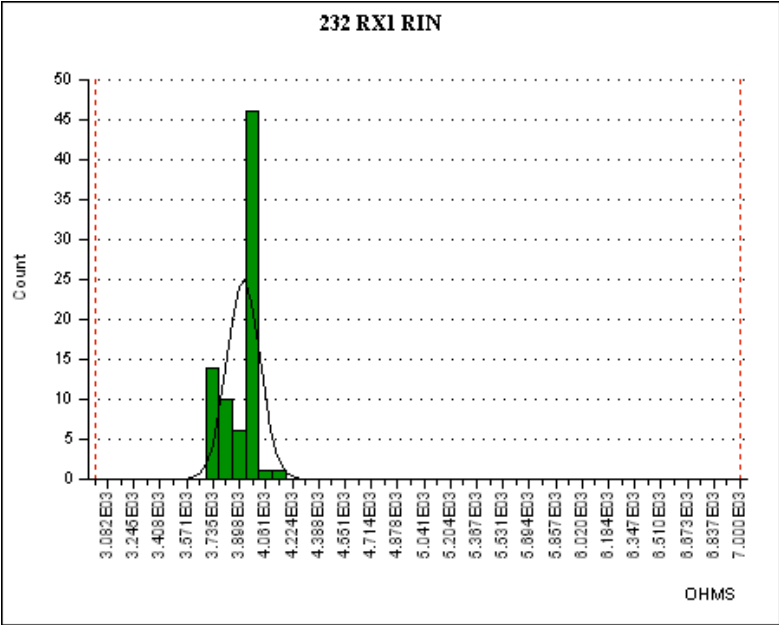
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=2.000, Test.Name=232 RX1 RIN



Statistics: (OHMS)

Max	4.180E03	25%	3.807E03	SpecHigh	7.000E03
Mean	3.910E03	10%	3.758E03	SpecLow	3.000E03
Min	3.704E03	N	78	PctWithinSpec	100.00
Range	475.130	Cp	>4.0000	PctDefSpec	0
StdDev	101.191	Cpl	2.9962	NWithinSpec	78
W	0.8752	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	2.9962		
90%	4.003E03	Skew	-0.4830		
75%	3.978E03	Kurtosis	-0.5607		
Median	3.954E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

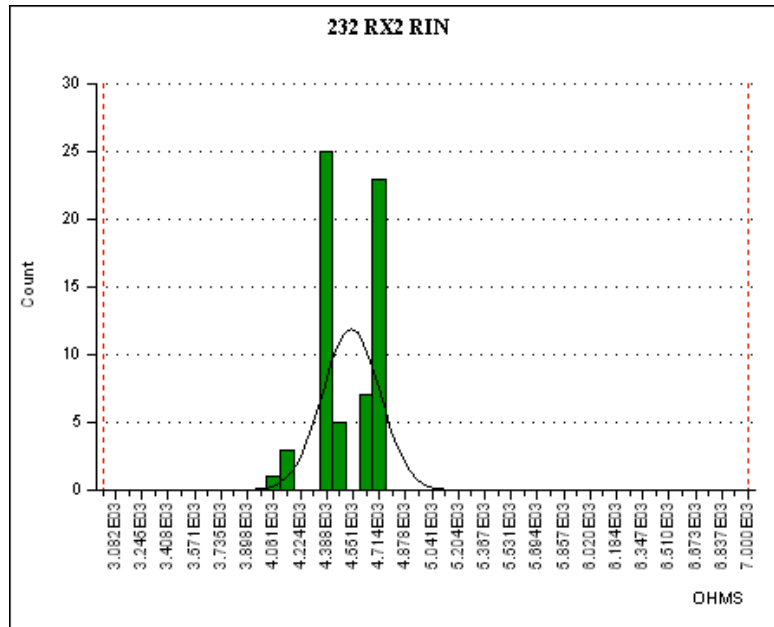
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=2.001, Test.Name=232 RX2 RIN



Statistics: (OHMS)

Max	4.749E03	25%	4.400E03	SpecHigh	7.000E03
Mean	4.522E03	10%	4.379E03	SpecLow	3.000E03
Min	4.093E03	N	64	PctWithinSpec	100.00
Range	656.152	Cp	3.8084	c	
StdDev	175.050	Cpl	2.8985	PctDefSpec	0
W	0.8574	Cpu	>4.0000	NWithinSpec	64
WpValue	0.0000	Cpk	2.8985	NOutsideSpec	0
90%	4.712E03	Skew	-0.4827		
75%	4.685E03	Kurtosis	-0.5095		
Median	4.454E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

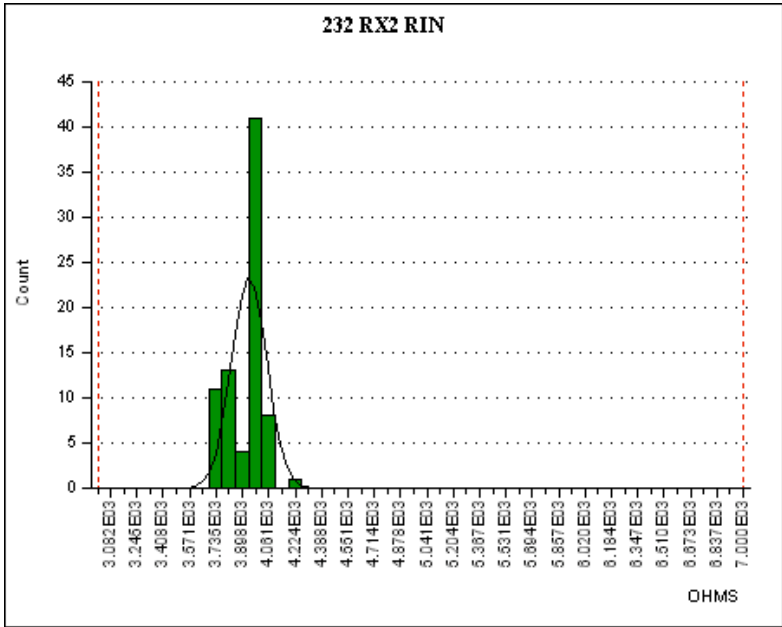
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=2.001, Test.Name=232 RX2 RIN



Statistics: (OHMS)

Max	4.230E03	25%	3.812E03	SpecHigh	7.000E03
Mean	3.926E03	10%	3.758E03	SpecLow	3.000E03
Min	3.714E03	N	78	PctWithinSpec	100.00
Range	516.030	Cp	>4.0000	c	
StdDev	108.780	Cpl	2.8376	PctDefSpec	0
W	0.8851	Cpu	>4.0000	NWithinSpec	78
WpValue	0.0000	Cpk	2.8376	NOutsideSpec	0
90%	4.023E03	Skew	-0.3685		
75%	3.999E03	Kurtosis	-0.5493		
Median	3.970E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

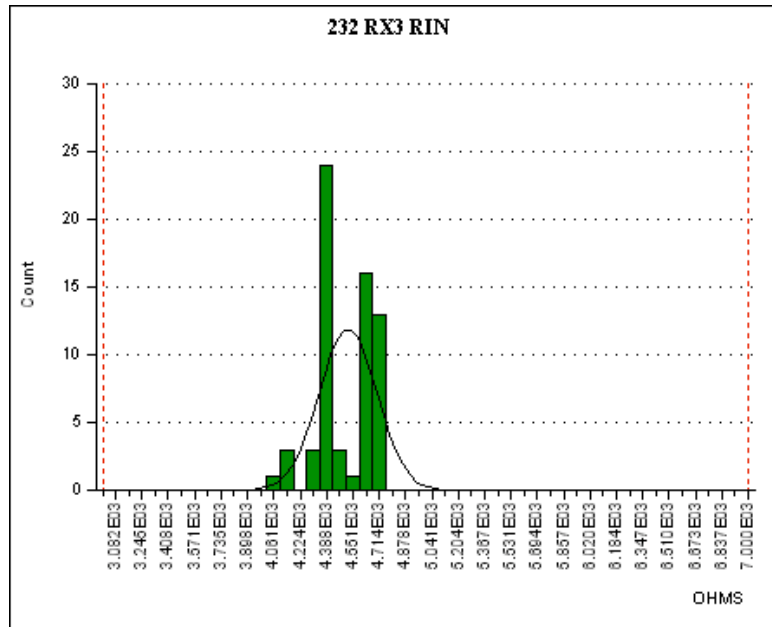
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=2.002, Test.Name=232 RX3 RIN



Statistics: (OHMS)

Max	4.744E03	25%	4.379E03	SpecHigh	7.000E03
Mean	4.503E03	10%	4.327E03	SpecLow	3.000E03
Min	4.082E03	N	64	PctWithinSpec	100.00
Range	662.079	Cp	3.8043	c	
StdDev	175.239	Cpl	2.8586	PctDefSpec	0
W	0.8796	Cpu	>4.0000	NWithinSpec	64
WpValue	0.0000	Cpk	2.8586	NOutsideSpec	0
90%	4.696E03	Skew	-0.4015		
75%	4.669E03	Kurtosis	-0.6997		
Median	4.440E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

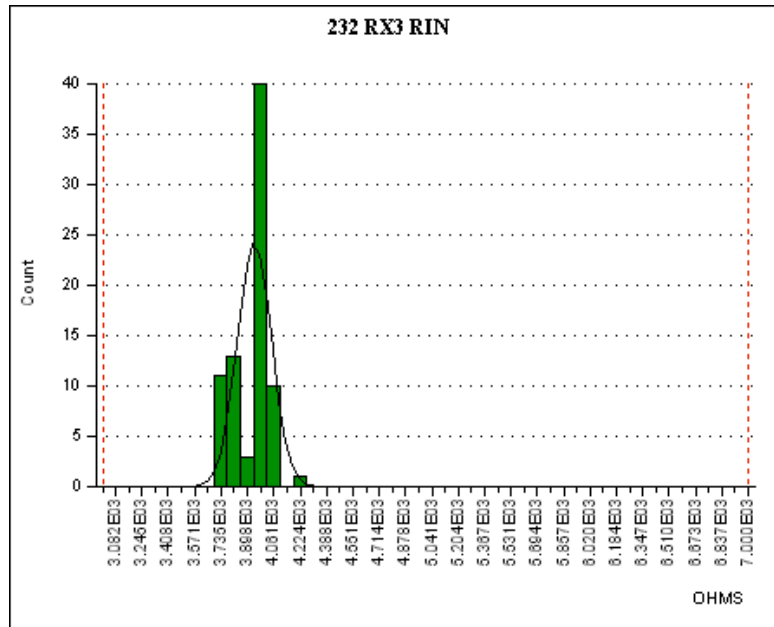
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=2.002, Test.Name=232 RX3 RIN



Statistics: (OHMS)

Max	4.217E03	25%	3.823E03	SpecHigh	7.000E03
Mean	3.928E03	10%	3.770E03	SpecLow	3.000E03
Min	3.725E03	N	78	PctWithinSpec	100.00
Range	492.503	Cp	>4.0000	PctDefSpec	0
StdDev	104.947	Cpl	2.9467	NWithinSpec	78
W	0.8894	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	2.9467		
90%	4.027E03	Skew	-0.3940		
75%	3.998E03	Kurtosis	-0.5393		
Median	3.968E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

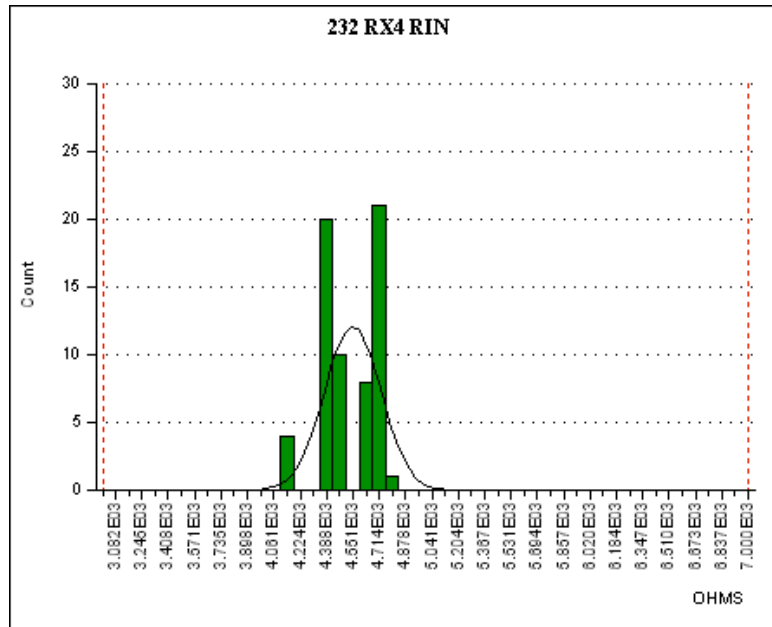
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=2.003, Test.Name=232 RX4 RIN



Statistics: (OHMS)

Max	4.762E03	25%	4.406E03	SpecHigh	7.000E03
Mean	4.532E03	10%	4.378E03	SpecLow	3.000E03
Min	4.108E03	N	64	PctWithinSpec	100.00
Range	653.648	Cp	3.8784	c	
StdDev	171.890	Cpl	2.9703	PctDefSpec	0
W	0.8742	Cpu	>4.0000	NWithinSpec	64
WpValue	0.0000	Cpk	2.9703	NOutsideSpec	0
90%	4.729E03	Skew	-0.4181		
75%	4.694E03	Kurtosis	-0.6573		
Median	4.461E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

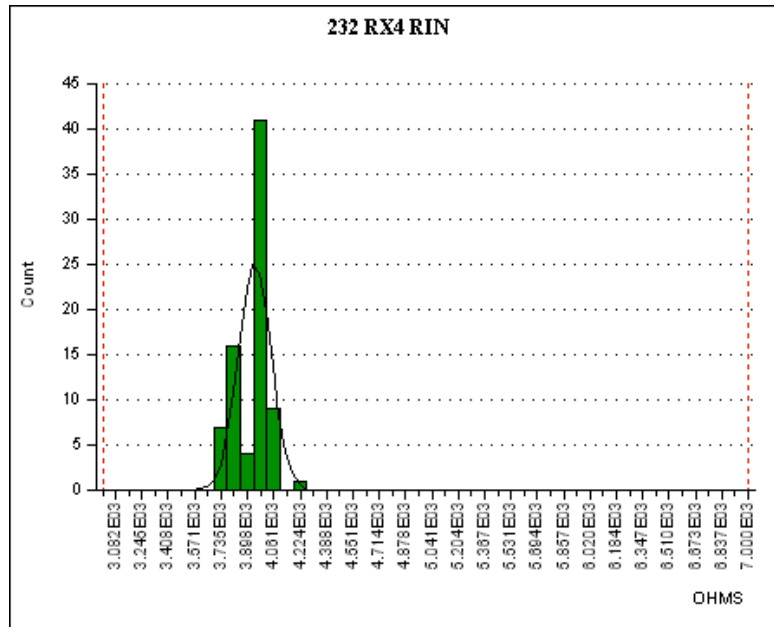
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=2.003, Test.Name=232 RX4 RIN



Statistics: (OHMS)

Max	4.223E03	25%	3.831E03	SpecHigh	7.000E03
Mean	3.929E03	10%	3.782E03	SpecLow	3.000E03
Min	3.732E03	N	78	PctWithinSpec	100.00
Range	491.687	Cp	>4.0000	c	
StdDev	100.907	Cpl	3.0704	PctDefSpec	0
W	0.8857	Cpu	>4.0000	NWithinSpec	78
WpValue	0.0000	Cpk	3.0704	NOutsideSpec	0
90%	4.027E03	Skew	-0.3885		
75%	3.999E03	Kurtosis	-0.3035		
Median	3.969E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

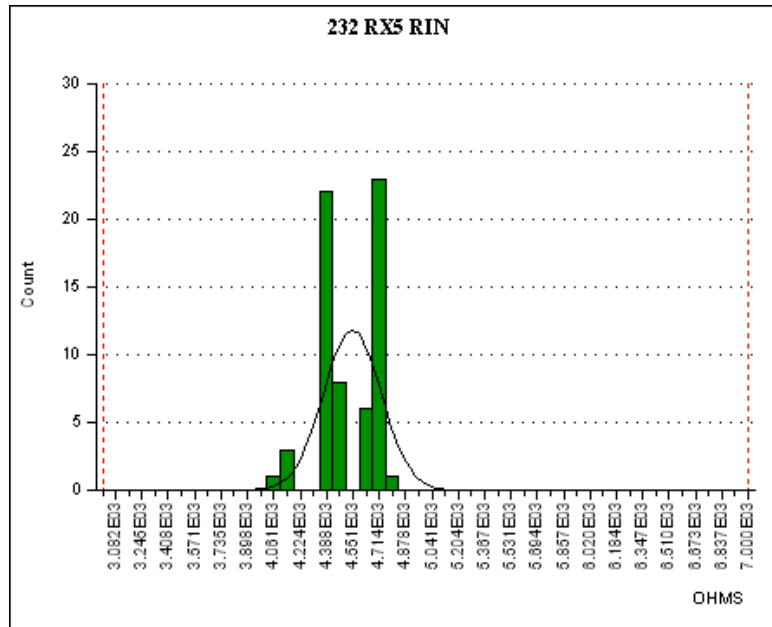
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=2.004, Test.Name=232 RX5 RIN



Statistics: (OHMS)

Max	4.761E03	25%	4.402E03	SpecHigh	7.000E03
Mean	4.529E03	10%	4.375E03	SpecLow	3.000E03
Min	4.091E03	N	64	PctWithinSpec	100.00
Range	669.992	Cp	3.7825	PctDefSpec	0
StdDev	176.250	Cpl	2.8911	NWithinSpec	64
W	0.8722	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	2.8911		
90%	4.730E03	Skew	-0.4176		
75%	4.693E03	Kurtosis	-0.6630		
Median	4.463E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

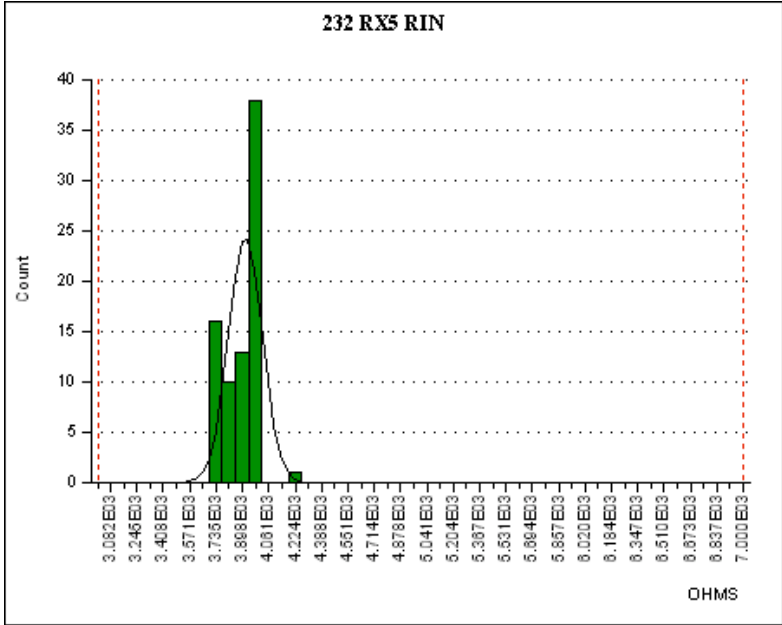
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=2.004, Test.Name=232 RX5 RIN



Statistics: (OHMS)

Max	4.208E03	25%	3.789E03	SpecHigh	7.000E03
Mean	3.903E03	10%	3.751E03	SpecLow	3.000E03
Min	3.703E03	N	78	PctWithinSpec	100.00
Range	505.095	Cp	>4.0000	PctDefSpec	0
StdDev	103.775	Cpl	2.9003	NWithinSpec	78
W	0.8714	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	2.9003		
90%	3.995E03	Skew	-0.3546		
75%	3.975E03	Kurtosis	-0.3738		
Median	3.941E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

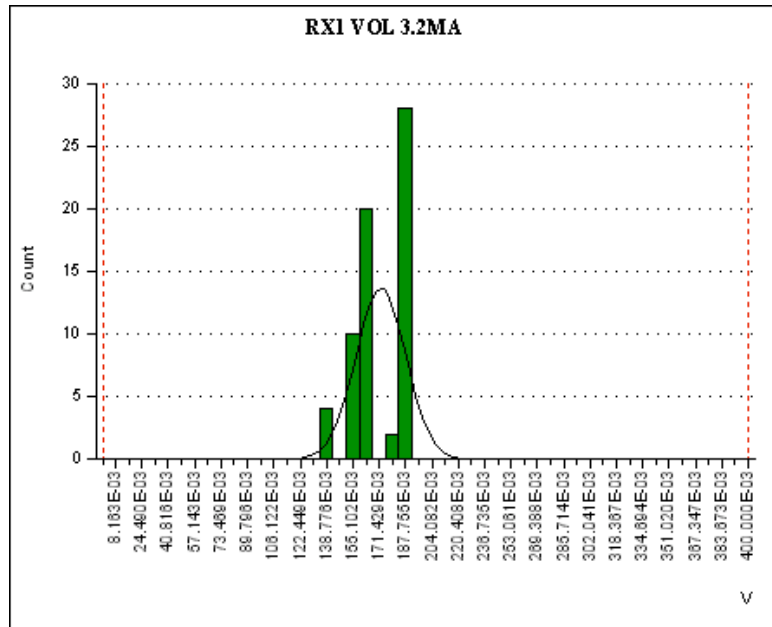
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=3.000, Test.Name=RX1 VOL 3.2MA



Statistics: (V)

Max	187.123E-03	25%	159.387E-03	SpecHigh	400.000E-03
Mean	170.290E-03	10%	157.976E-03	SpecLow	0
Min	135.899E-03	N	64	PctWithinSpec	100.00
Range	51.224E-03	Cp	>4.0000	PctDefSpec	0
StdDev	15.226E-03	Cpl	3.7279	NWithinSpec	64
W	0.7926	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	3.7279		
90%	186.551E-03	Skew	-0.3110		
75%	185.350E-03	Kurtosis	-1.0749		
Median	160.607E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

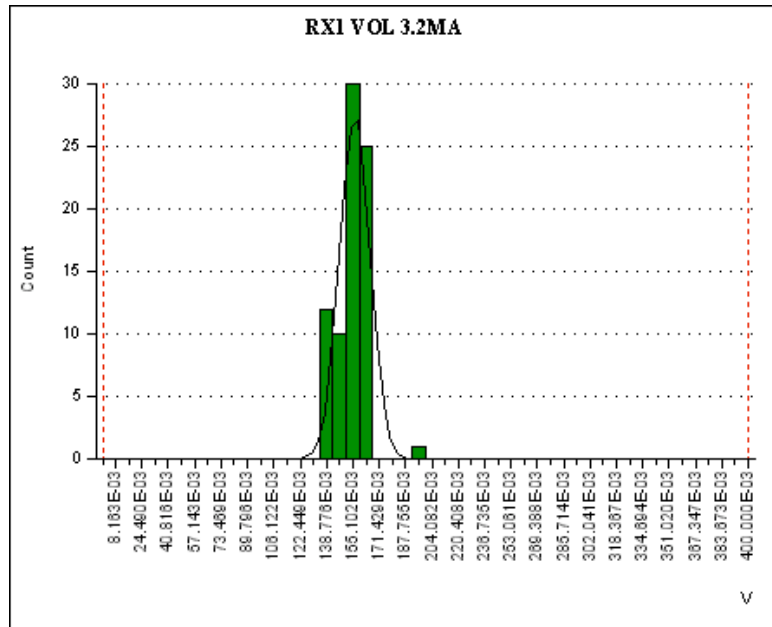
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.000, Test.Name=RX1 VOL 3.2MA



Statistics: (V)

Max	192.421E-03	25%	149.470E-03	SpecHigh	400.000E-03
Mean	154.381E-03	10%	139.979E-03	SpecLow	0
Min	135.445E-03	N	78	PctWithinSpec	100.00
Range	56.976E-03	Cp	>4.0000	c	
StdDev	9.247E-03	Cpl	>4.0000	PctDefSpec	0
W	0.8834	Cpu	>4.0000	NWithinSpec	78
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	161.893E-03	Skew	0.2005		
75%	159.951E-03	Kurtosis	2.6768		
Median	157.225E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

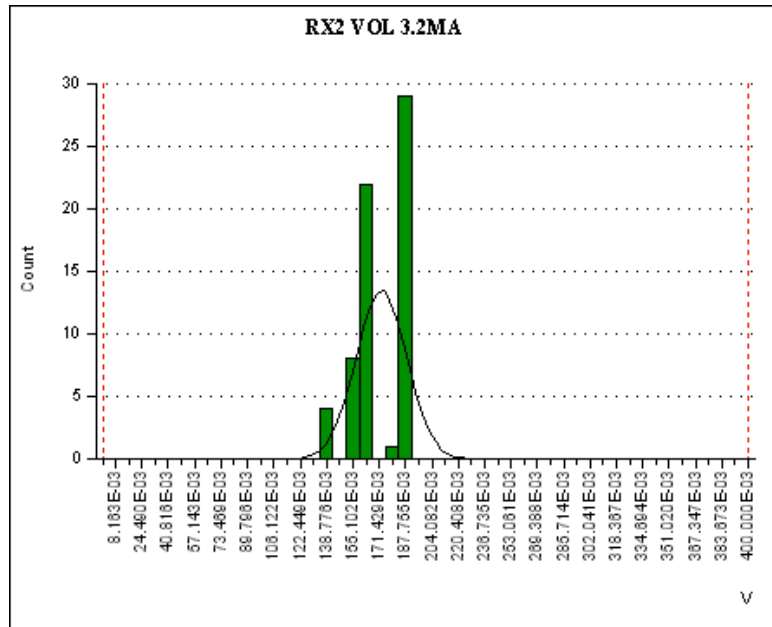
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.001, Test.Name=RX2 VOL 3.2MA



Statistics: (V)

Max	188.646E-03	25%	159.387E-03	SpecHigh	400.000E-03
Mean	170.709E-03	10%	158.739E-03	SpecLow	0
Min	136.242E-03	N	64	PctWithinSpec	100.00
Range	52.404E-03	Cp	>4.0000	PctDefSpec	0
StdDev	15.496E-03	Cpl	3.6721	NWithinSpec	64
W	0.7944	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	3.6721		
90%	187.123E-03	Skew	-0.3027		
75%	185.903E-03	Kurtosis	-1.0857		
Median	160.969E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

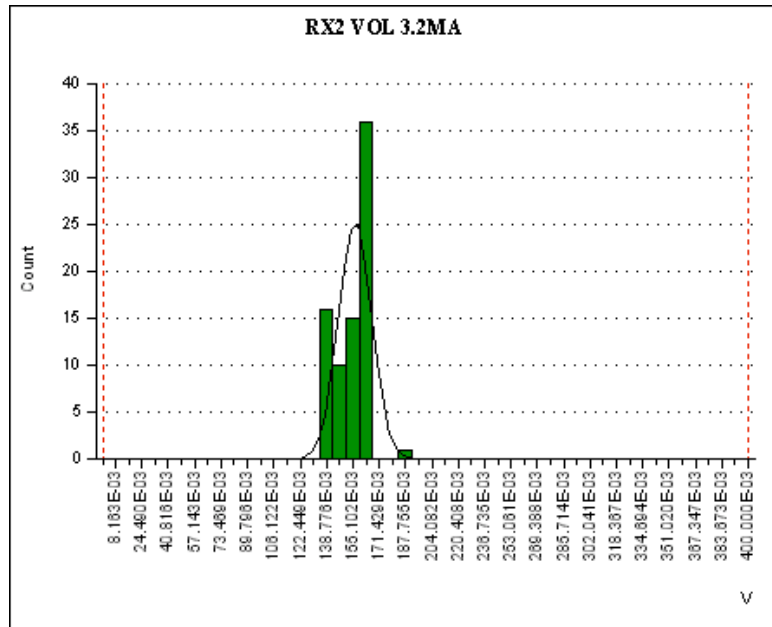
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.001, Test.Name=RX2 VOL 3.2MA



Statistics: (V)

Max	190.934E-03	25%	144.096E-03	SpecHigh	400.000E-03
Mean	154.577E-03	10%	140.932E-03	SpecLow	0
Min	136.055E-03	N	78	PctWithinSpec	100.00
Range	54.880E-03	Cp	>4.0000	c	
StdDev	10.083E-03	Cpl	>4.0000	PctDefSpec	0
W	0.8741	Cpu	>4.0000	NWithinSpec	78
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	163.800E-03	Skew	0.0163		
75%	161.512E-03	Kurtosis	0.7180		
Median	157.739E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

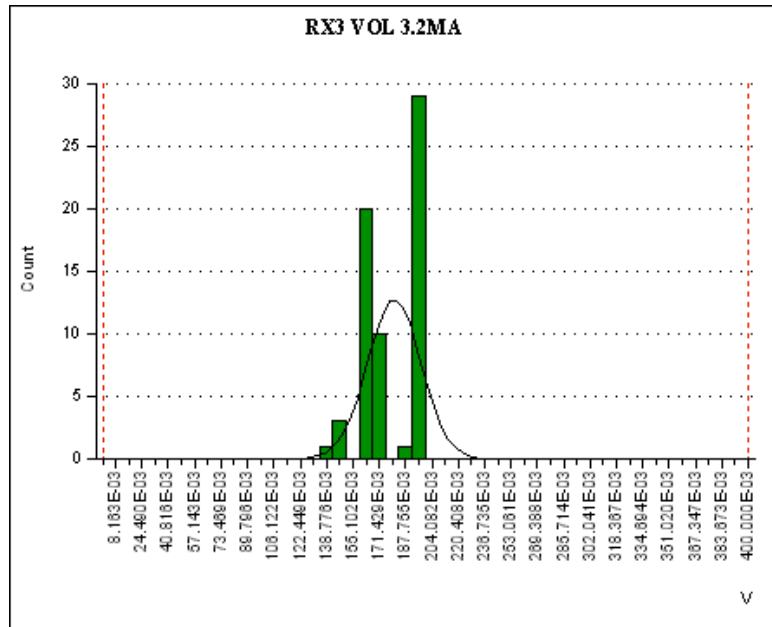
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.002, Test.Name=RX3 VOL 3.2MA



Statistics: (V)

Max	196.878E-03	25%	166.856E-03	SpecHigh	400.000E-03
Mean	178.580E-03	10%	165.904E-03	SpecLow	0
Min	140.625E-03	N	64	PctWithinSpec	100.00
Range	56.253E-03	Cp	>4.0000	PctDefSpec	0
StdDev	16.360E-03	Cpl	3.6386	NWithinSpec	64
W	0.7933	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	3.6386		
90%	195.660E-03	Skew	-0.3447		
75%	194.897E-03	Kurtosis	-0.9788		
Median	168.247E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

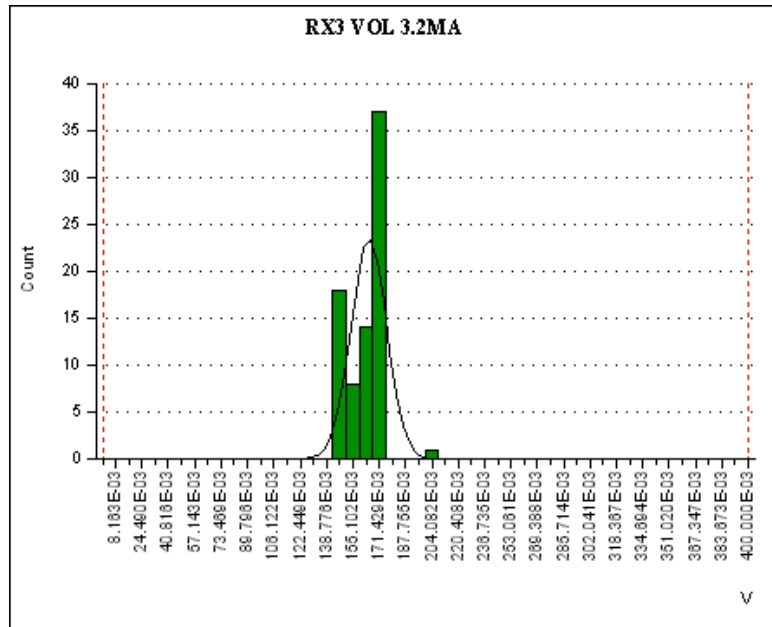
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.002, Test.Name=RX3 VOL 3.2MA



Statistics: (V)

Max	201.225E-03	25%	151.260E-03	SpecHigh	400.000E-03
Mean	163.014E-03	10%	147.297E-03	SpecLow	0
Min	143.333E-03	N	78	PctWithinSpec	100.00
Range	57.891E-03	Cp	>4.0000	c	
StdDev	10.846E-03	Cpl	>4.0000	PctDefSpec	0
W	0.8549	Cpu	>4.0000	NWithinSpec	78
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	172.336E-03	Skew	-0.0653		
75%	170.241E-03	Kurtosis	0.5226		
Median	167.172E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

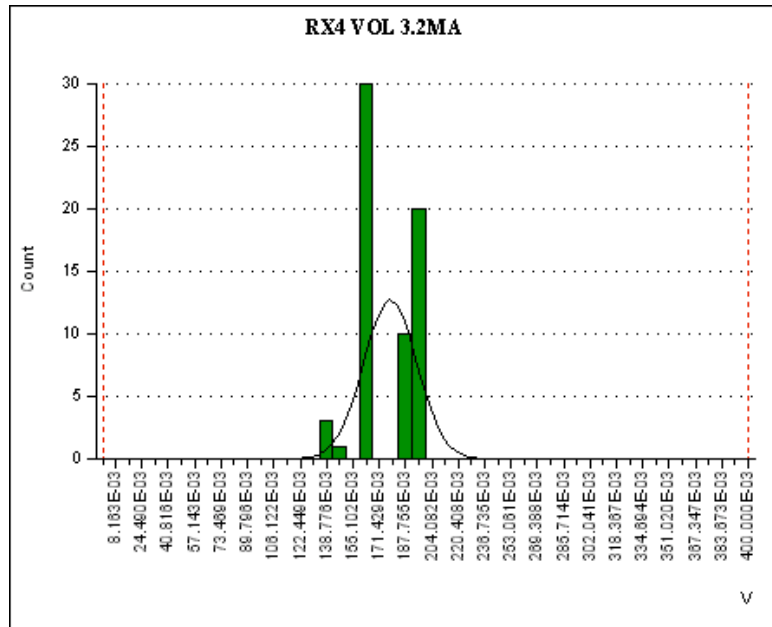
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.003, Test.Name=RX4 VOL 3.2MA



Statistics: (V)

Max	194.783E-03	25%	163.998E-03	SpecHigh	400.000E-03
Mean	176.112E-03	10%	163.312E-03	SpecLow	0
Min	139.328E-03	N	64	PctWithinSpec	100.00
Range	55.454E-03	Cp	>4.0000	PctDefSpec	0
StdDev	16.352E-03	Cpl	3.5901	NWithinSpec	64
W	0.7944	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	3.5901		
90%	193.067E-03	Skew	-0.3028		
75%	192.343E-03	Kurtosis	-1.0938		
Median	165.561E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

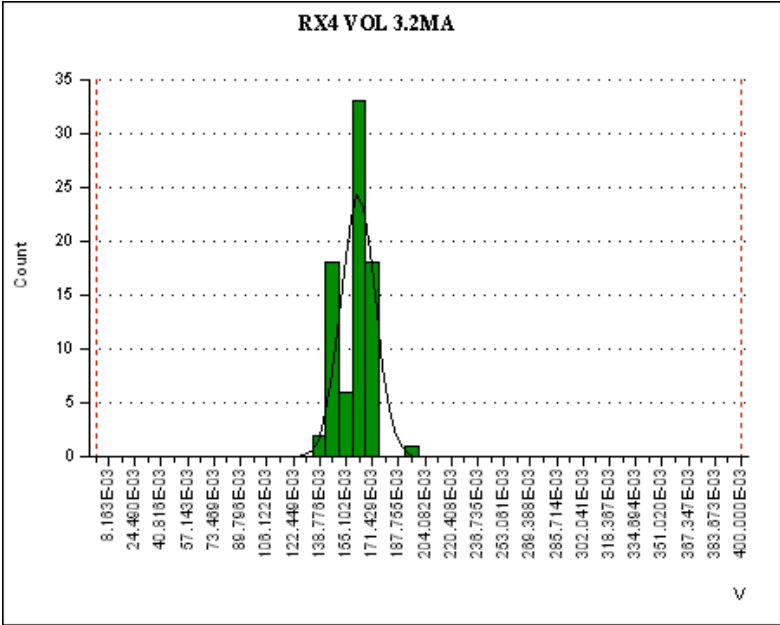
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.003, Test.Name=RX4 VOL 3.2MA



Statistics: (V)

Max	197.604E-03	25%	150.003E-03	SpecHigh	400.000E-03
Mean	160.666E-03	10%	145.506E-03	SpecLow	0
Min	141.504E-03	N	78	PctWithinSpec	100.00
Range	56.101E-03	Cp	>4.0000	c	
StdDev	10.396E-03	Cpl	>4.0000	PctDefSpec	0
W	0.8544	Cpu	>4.0000	NWithinSpec	78
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	169.517E-03	Skew	-0.0829		
75%	167.267E-03	Kurtosis	0.6564		
Median	165.248E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

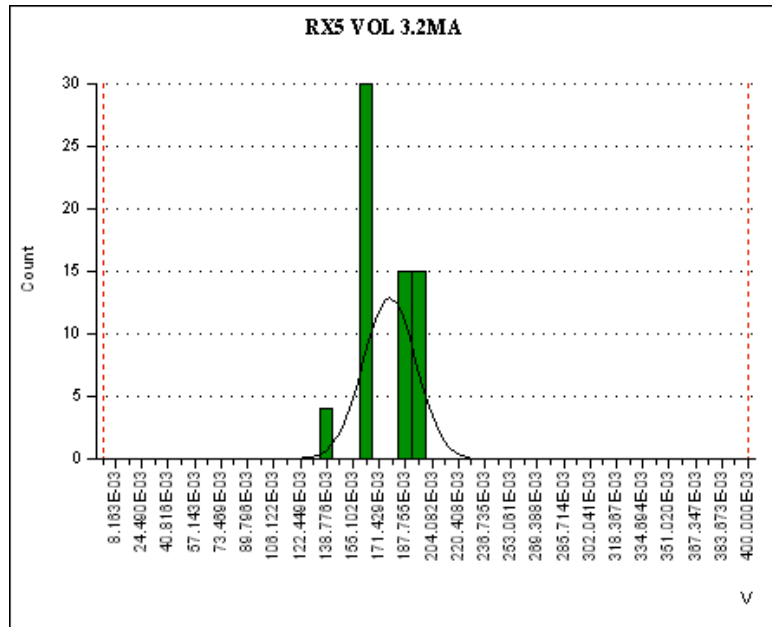
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=3.004, Test.Name=RX5 VOL 3.2MA



Statistics: (V)

Max	194.173E-03	25%	163.922E-03	SpecHigh	400.000E-03
Mean	175.726E-03	10%	163.046E-03	SpecLow	0
Min	139.252E-03	N	64	PctWithinSpec	100.00
Range	54.921E-03	Cp	>4.0000	PctDefSpec	0
StdDev	16.127E-03	Cpl	3.6321	NWithinSpec	64
W	0.8002	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	3.6321		
90%	192.800E-03	Skew	-0.3322		
75%	191.697E-03	Kurtosis	-1.0156		
Median	166.209E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

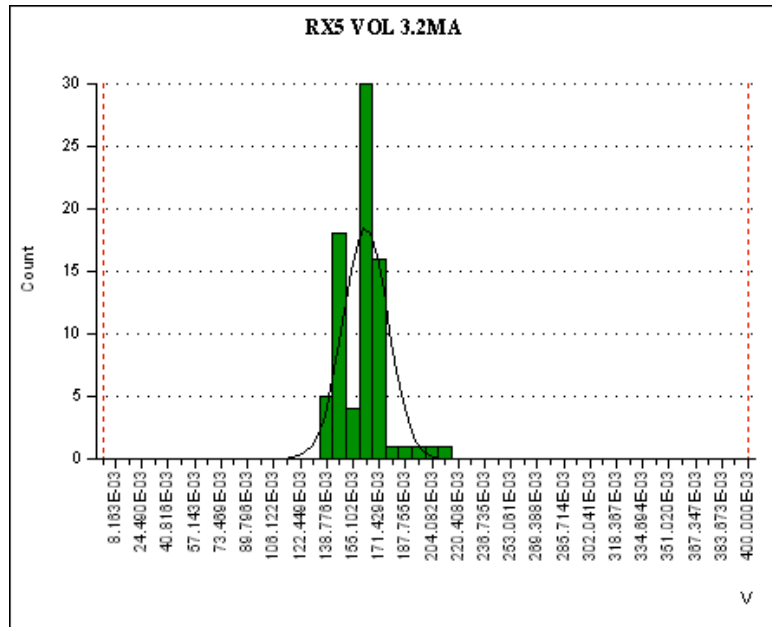
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.004, Test.Name=RX5 VOL 3.2MA



Statistics: (V)

Max	211.706E-03	25%	147.945E-03	SpecHigh	400.000E-03
Mean	160.978E-03	10%	143.829E-03	SpecLow	0
Min	140.246E-03	N	78	PctWithinSpec	100.00
Range	71.460E-03	Cp	>4.0000	PctDefSpec	0
StdDev	13.714E-03	Cpl	3.9127	NWithinSpec	78
W	0.8849	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	3.9127		
90%	170.775E-03	Skew	0.9101		
75%	167.458E-03	Kurtosis	2.2532		
Median	163.456E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

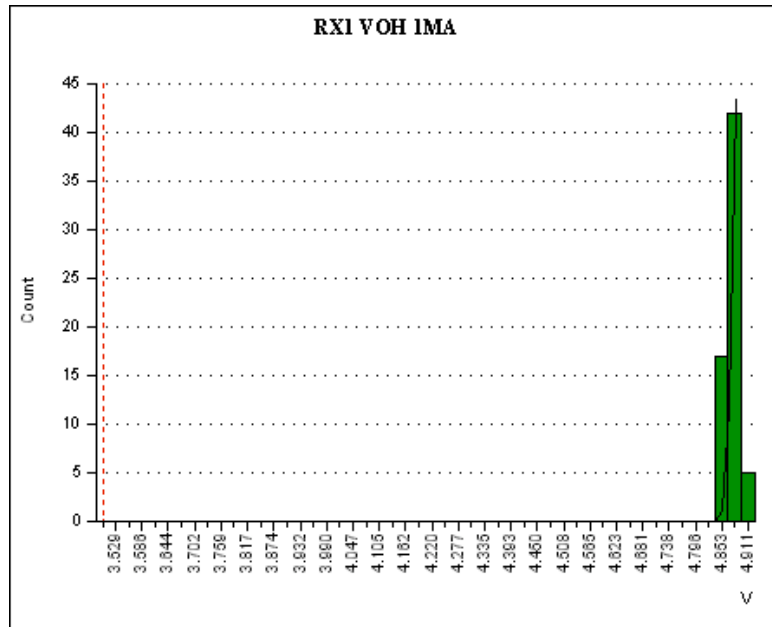
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.005, Test.Name=RX1 VOH 1MA



Statistics: (V)

Max	4.911	25%	4.867	SpecHigh	N/A
Mean	4.878	10%	4.863	SpecLow	3.500
Min	4.857	N	64	PctWithinSpec	100.00
Range	53.510E-03	Cp	N/A	PctDefSpec	0
StdDev	13.237E-03	Cpl	>4.0000	NWithinSpec	64
W	0.9485	Cpu	N/A	NOutsideSpec	0
WpValue	0.0097	Cpk	>4.0000		
90%	4.894	Skew	0.5607		
75%	4.887	Kurtosis	-0.3337		
Median	4.878				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

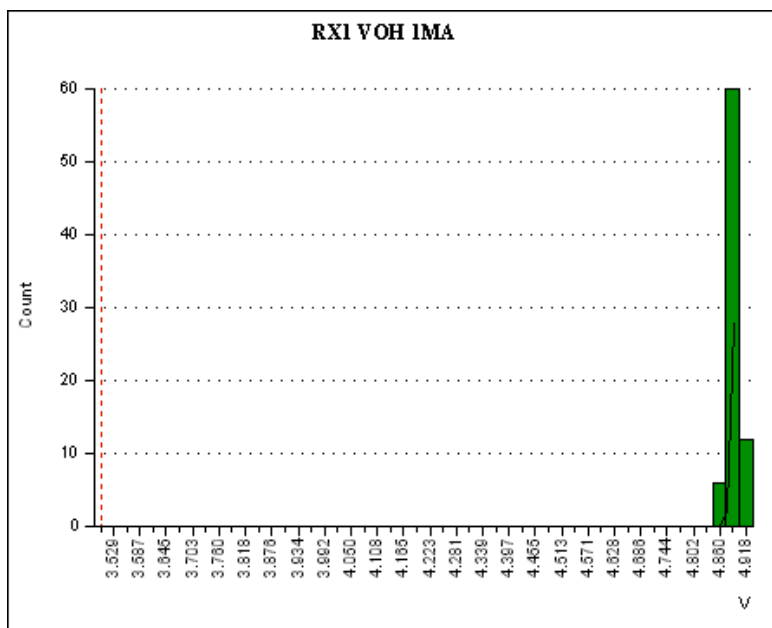
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=3.005, Test.Name=RX1 VOH 1MA



Statistics: (V)

Max	4.918	25%	4.885	SpecHigh	N/A
Mean	4.892	10%	4.876	SpecLow	3.500
Min	4.865	N	78	PctWithinSpec	100.00
Range	52.710E-03	Cp	N/A	PctDefSpec	0
StdDev	11.472E-03	Cpl	>4.0000	NWithinSpec	78
W	0.9871	Cpu	N/A	NOutsideSpec	0
WpValue	0.6255	Cpk	>4.0000		
90%	4.908	Skew	0.0659		
75%	4.900	Kurtosis	-0.1991		
Median	4.891				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

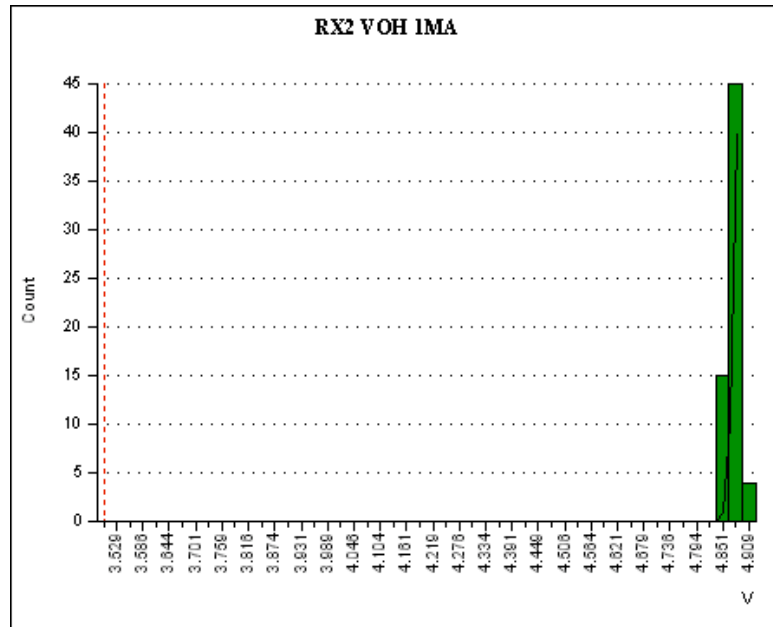
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.006, Test.Name=RX2 VOH 1MA



Statistics: (V)

Max	4.909	25%	4.866	SpecHigh	N/A
Mean	4.877	10%	4.863	SpecLow	3.500
Min	4.854	N	64	PctWithinSpec	100.00
Range	54.347E-03	Cp	N/A	PctDefSpec	0
StdDev	13.501E-03	Cpl	>4.0000	NWithinSpec	64
W	0.9431	Cpu	N/A	NOutsideSpec	0
WpValue	0.0053	Cpk	>4.0000		
90%	4.894	Skew	0.4983		
75%	4.887	Kurtosis	-0.5685		
Median	4.874				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

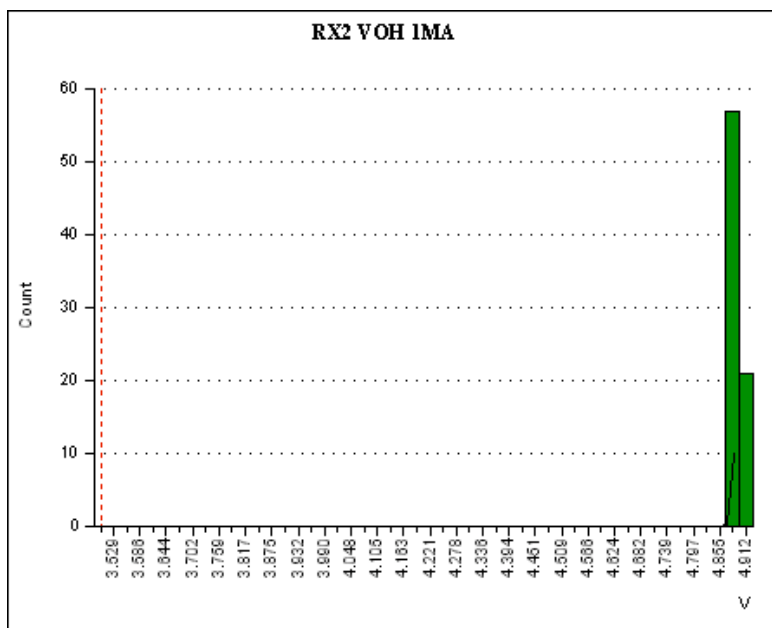
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.006, Test.Name=RX2 VOH 1MA



Statistics: (V)

Max	4.912	25%	4.884	SpecHigh	N/A
Mean	4.891	10%	4.879	SpecLow	3.500
Min	4.870	N	78	PctWithinSpec	100.00
Range	42.381E-03	Cp	N/A	c	
StdDev	10.268E-03	Cpl	>4.0000	PctDefSpec	0
W	0.9793	Cpu	N/A	NWithinSpec	78
WpValue	0.2352	Cpk	>4.0000	NOutsideSpec	0
90%	4.907	Skew	0.2083		
75%	4.899	Kurtosis	-0.6701		
Median	4.890				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

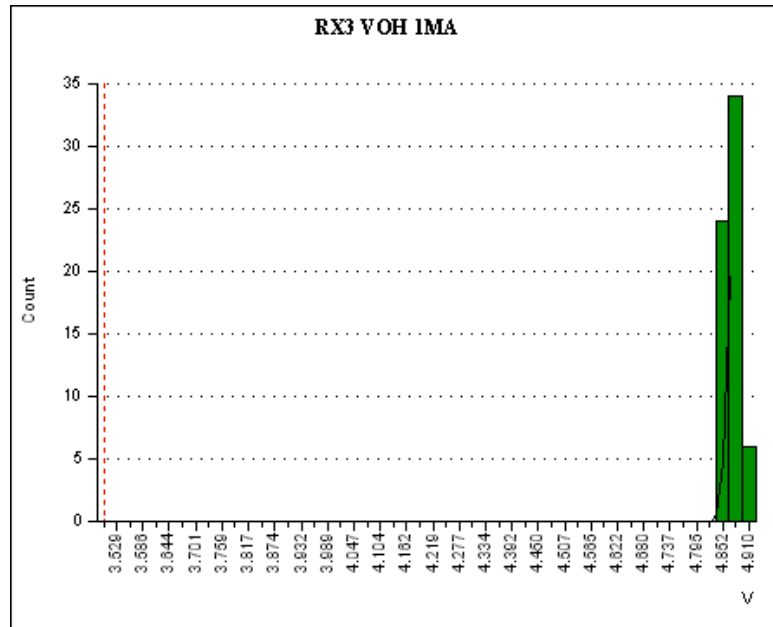
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.007, Test.Name=RX3 VOH 1MA



Statistics: (V)

Max	4.910	25%	4.861	SpecHigh	N/A
Mean	4.875	10%	4.854	SpecLow	3.500
Min	4.844	N	64	PctWithinSpec	100.00
Range	65.857E-03	Cp	N/A	PctDefSpec	0
StdDev	16.676E-03	Cpl	>4.0000	NWithinSpec	64
W	0.9738	Cpu	N/A	NOutsideSpec	0
WpValue	0.1899	Cpk	>4.0000		
90%	4.896	Skew	0.0908		
75%	4.888	Kurtosis	-0.9320		
Median	4.875				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

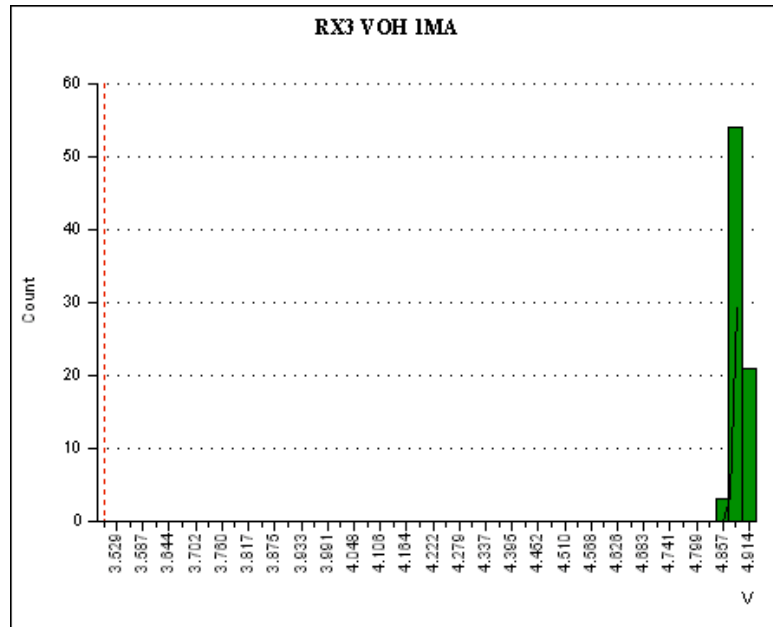
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.007, Test.Name=RX3 VOH 1MA



Statistics: (V)

Max	4.914	25%	4.881	SpecHigh	N/A
Mean	4.888	10%	4.877	SpecLow	3.500
Min	4.861	N	78	PctWithinSpec	100.00
Range	52.860E-03	Cp	N/A	c	
StdDev	12.305E-03	Cpl	>4.0000	PctDefSpec	0
W	0.9200	Cpu	N/A	NWithinSpec	78
WpValue	0.0001	Cpk	>4.0000	NOutsideSpec	0
90%	4.907	Skew	0.4652		
75%	4.902	Kurtosis	-0.5111		
Median	4.885				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

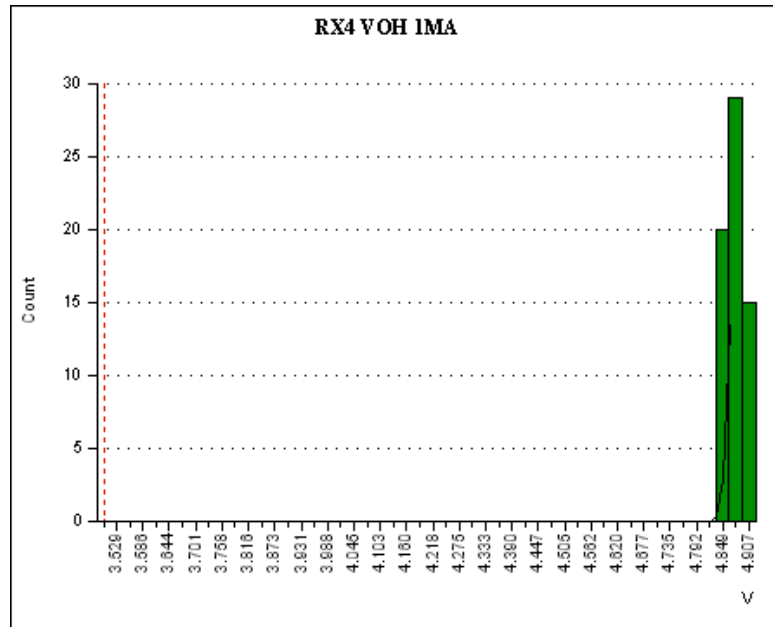
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=3.008, Test.Name=RX4 VOH 1MA



Statistics: (V)

Max	4.907	25%	4.861	SpecHigh	N/A
Mean	4.877	10%	4.856	SpecLow	3.500
Min	4.848	N	64	PctWithinSpec	100.00
Range	58.541E-03	Cp	N/A	PctDefSpec	0
StdDev	17.418E-03	Cpl	>4.0000	NWithinSpec	64
W	0.9432	Cpu	N/A	NOutsideSpec	0
WpValue	0.0054	Cpk	>4.0000		
90%	4.900	Skew	0.0449		
75%	4.892	Kurtosis	-1.2920		
Median	4.877				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

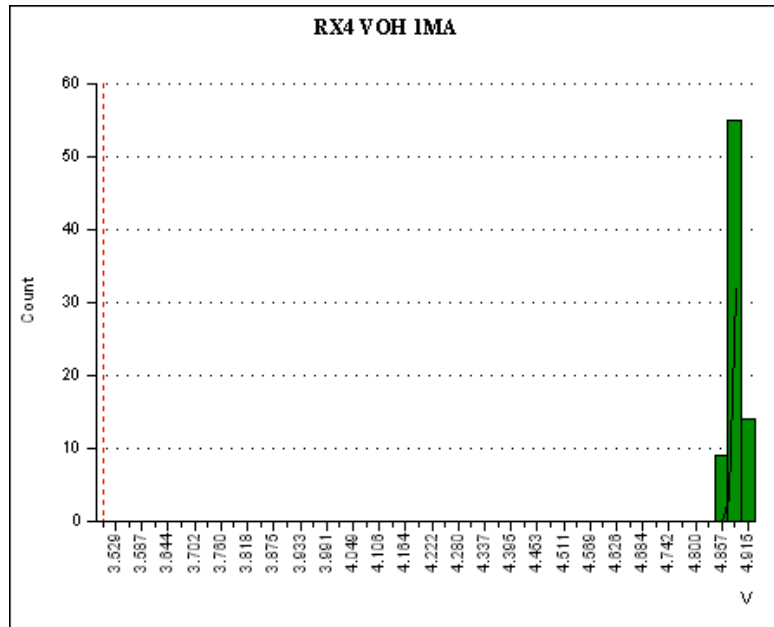
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.008, Test.Name=RX4 VOH 1MA



Statistics: (V)

Max	4.915	25%	4.882	SpecHigh	N/A
Mean	4.888	10%	4.871	SpecLow	3.500
Min	4.865	N	78	PctWithinSpec	100.00
Range	50.307E-03	Cp	N/A	PctDefSpec	0
StdDev	11.816E-03	Cpl	>4.0000	NWithinSpec	78
W	0.9757	Cpu	N/A	NOutsideSpec	0
WpValue	0.1418	Cpk	>4.0000		
90%	4.905	Skew	0.1857		
75%	4.896	Kurtosis	-0.3319		
Median	4.886				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

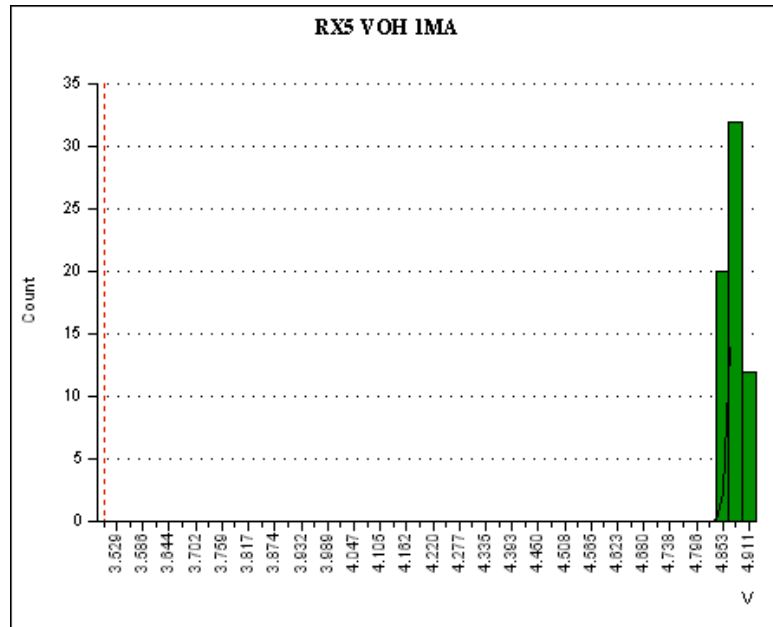
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.009, Test.Name=RX5 VOH 1MA



Statistics: (V)

Max	4.911	25%	4.866	SpecHigh	N/A
Mean	4.879	10%	4.861	SpecLow	3.500
Min	4.848	N	64	PctWithinSpec	100.00
Range	62.847E-03	Cp	N/A	PctDefSpec	0
StdDev	16.045E-03	Cpl	>4.0000	NWithinSpec	64
W	0.9615	Cpu	N/A	NOutsideSpec	0
WpValue	0.0436	Cpk	>4.0000		
90%	4.902	Skew	0.1894		
75%	4.892	Kurtosis	-1.0172		
Median	4.879				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

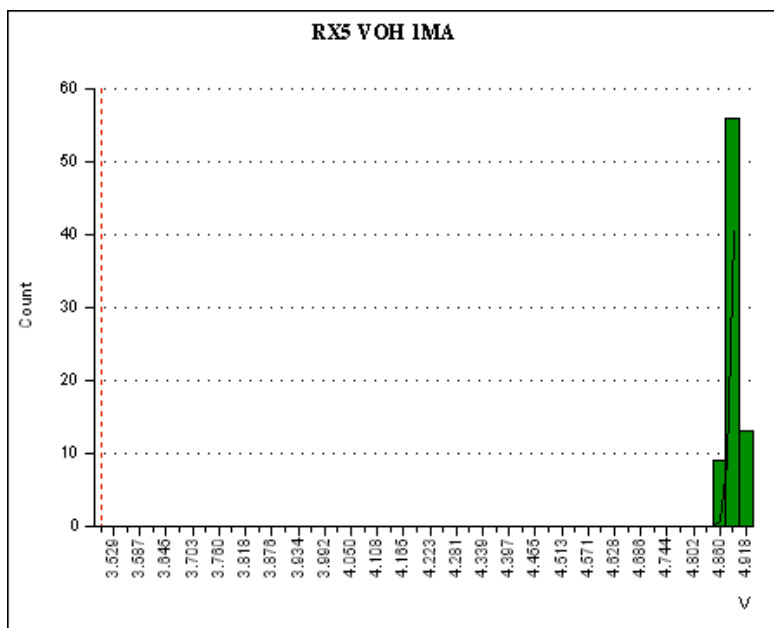
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.009, Test.Name=RX5 VOH 1MA



Statistics: (V)

Max	4.918	25%	4.880	SpecHigh	N/A
Mean	4.889	10%	4.873	SpecLow	3.500
Min	4.849	N	78	PctWithinSpec	100.00
Range	69.058E-03	Cp	N/A	c	
StdDev	13.828E-03	Cpl	>4.0000	PctDefSpec	0
W	0.9809	Cpu	N/A	NWithinSpec	78
WpValue	0.2935	Cpk	>4.0000	NOutsideSpec	0
90%	4.907	Skew	-0.0651		
75%	4.901	Kurtosis	0.1024		
Median	4.887				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

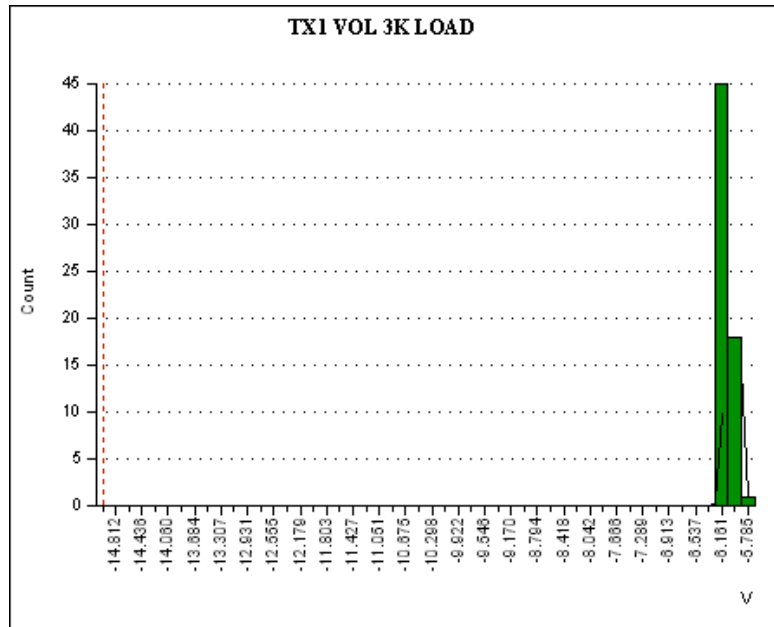
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.000, Test.Name=TX1 VOL 3K LOAD



Statistics: (V)

Max	-5.785	25%	-6.140	SpecHigh	N/A
Mean	-6.099	10%	-6.194	SpecLow	-15.000
Min	-6.230	N	64	PctWithinSpec	100.00
Range	444.815E-03	Cp	N/A	PctDefSpec	0
StdDev	76.132E-03	Cpl	>4.0000	NWithinSpec	64
W	0.9350	Cpu	N/A	NOutsideSpec	0
WpValue	0.0022	Cpk	>4.0000		
90%	-6.023	Skew	1.1025		
75%	-6.058	Kurtosis	3.5907		
Median	-6.104				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

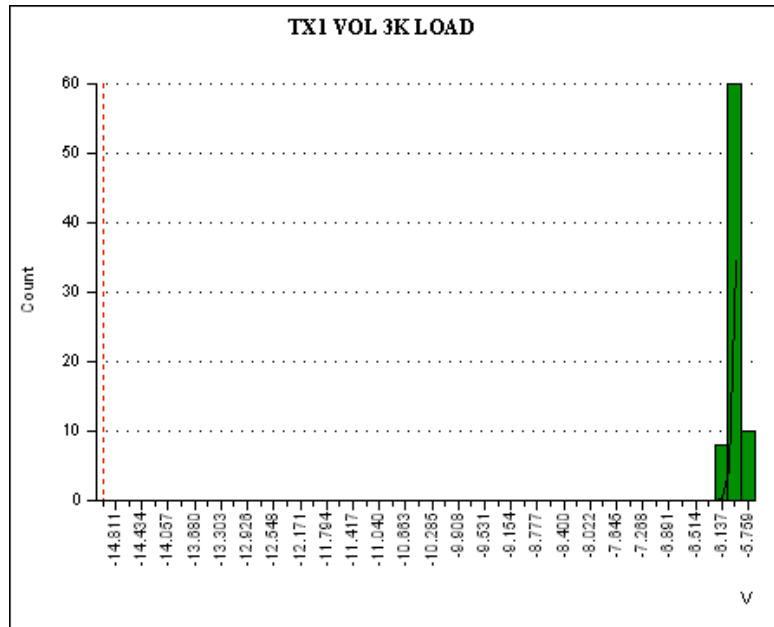
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.000, Test.Name=TX1 VOL 3K LOAD



Statistics: (V)

Max	-5.759	25%	-5.987	SpecHigh	N/A
Mean	-5.938	10%	-6.044	SpecLow	-15.000
Min	-6.206	N	78	PctWithinSpec	100.00
Range	446.568E-03	Cp	N/A	PctDefSpec	0
StdDev	81.097E-03	Cpl	>4.0000	NWithinSpec	78
W	0.9789	Cpu	N/A	NOutsideSpec	0
WpValue	0.2235	Cpk	>4.0000		
90%	-5.837	Skew	-0.3316		
75%	-5.897	Kurtosis	0.9692		
Median	-5.933				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

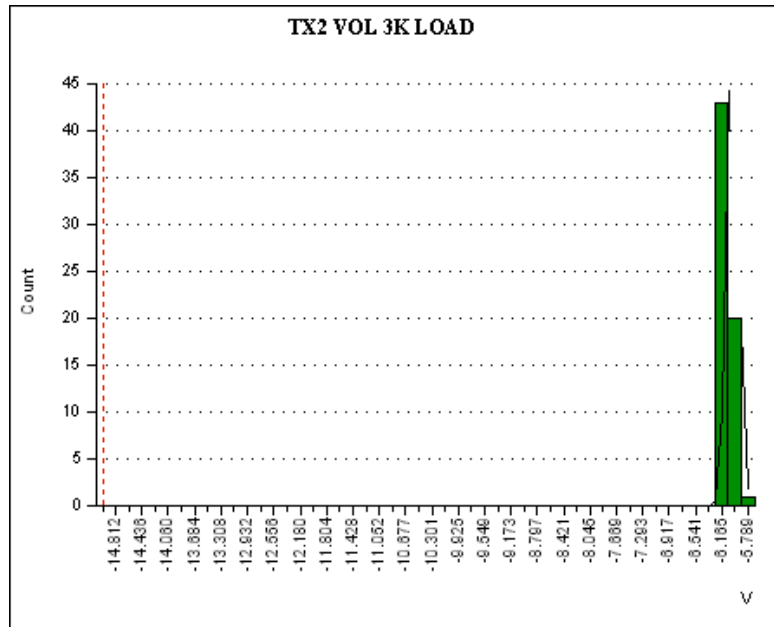
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.001, Test.Name=TX2 VOL 3K LOAD



Statistics: (V)

Max	-5.789	25%	-6.155	SpecHigh	N/A
Mean	-6.096	10%	-6.184	SpecLow	-15.000
Min	-6.248	N	64	PctWithinSpec	100.00
Range	458.755E-03	Cp	N/A	PctDefSpec	0
StdDev	81.620E-03	Cpl	>4.0000	NWithinSpec	64
W	0.9394	Cpu	N/A	NOutsideSpec	0
WpValue	0.0036	Cpk	>4.0000		
90%	-5.992	Skew	1.1234		
75%	-6.057	Kurtosis	2.5045		
Median	-6.107				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

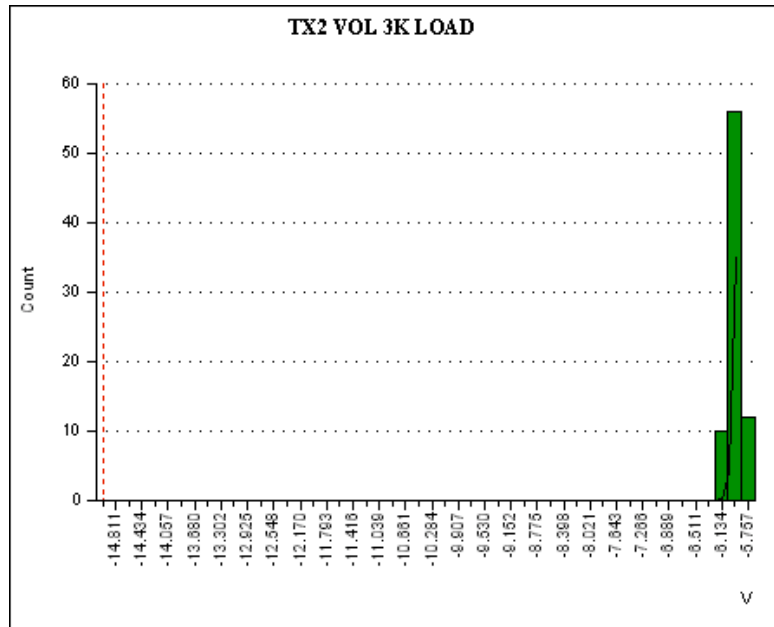
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.001, Test.Name=TX2 VOL 3K LOAD



Statistics: (V)

Max	-5.757	25%	-5.991	SpecHigh	N/A
Mean	-5.937	10%	-6.045	SpecLow	-15.000
Min	-6.145	N	78	PctWithinSpec	100.00
Range	388.453E-03	Cp	N/A	PctDefSpec	0
StdDev	79.190E-03	Cpl	>4.0000	NWithinSpec	78
W	0.9904	Cpu	N/A	NOutsideSpec	0
WpValue	0.8312	Cpk	>4.0000		
90%	-5.839	Skew	-0.1764		
75%	-5.899	Kurtosis	0.0217		
Median	-5.932				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

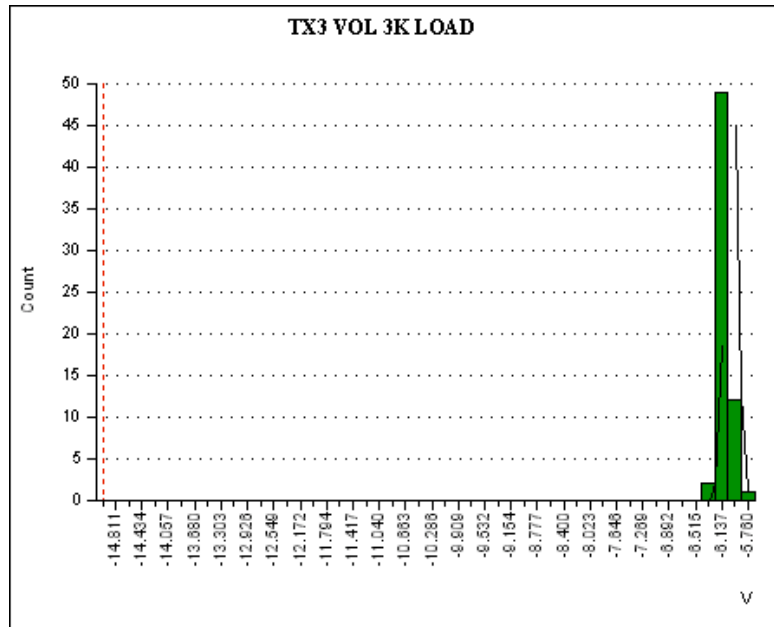
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.002, Test.Name=TX3 VOL 3K LOAD



Statistics: (V)

Max	-5.760	25%	-6.150	SpecHigh	N/A
Mean	-6.094	10%	-6.190	SpecLow	-15.000
Min	-6.240	N	64	PctWithinSpec	100.00
Range	480.007E-03	Cp	N/A	PctDefSpec	0
StdDev	86.387E-03	Cpl	>4.0000	NWithinSpec	64
W	0.9263	Cpu	N/A	NOutsideSpec	0
WpValue	0.0009	Cpk	>4.0000		
90%	-5.984	Skew	1.2205		
75%	-6.063	Kurtosis	2.8782		
Median	-6.108				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

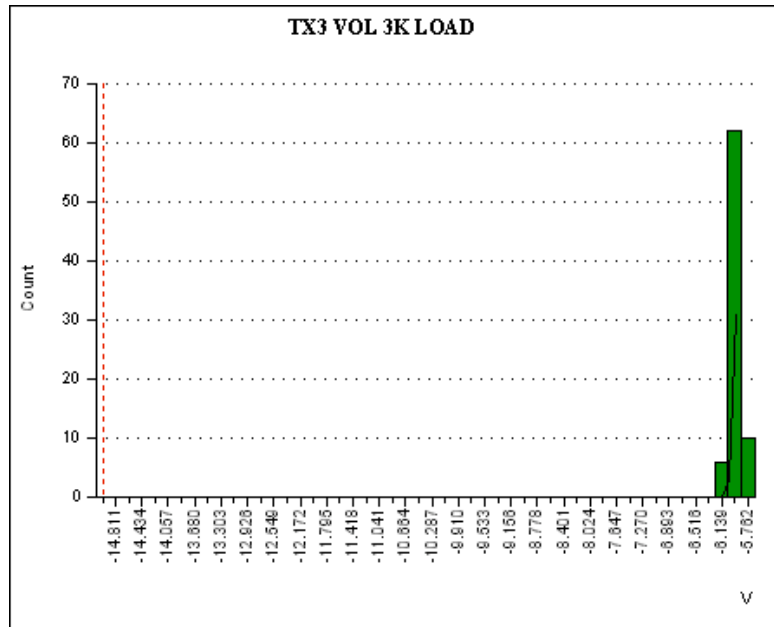
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.002, Test.Name=TX3 VOL 3K LOAD



Statistics: (V)

Max	-5.762	25%	-5.990	SpecHigh	N/A
Mean	-5.937	10%	-6.024	SpecLow	-15.000
Min	-6.116	N	78	PctWithinSpec	100.00
Range	354.102E-03	Cp	N/A	PctDefSpec	0
StdDev	75.569E-03	Cpl	>4.0000	NWithinSpec	78
W	0.9886	Cpu	N/A	NOutsideSpec	0
WpValue	0.7172	Cpk	>4.0000		
90%	-5.823	Skew	-0.0475		
75%	-5.892	Kurtosis	-0.0532		
Median	-5.933				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

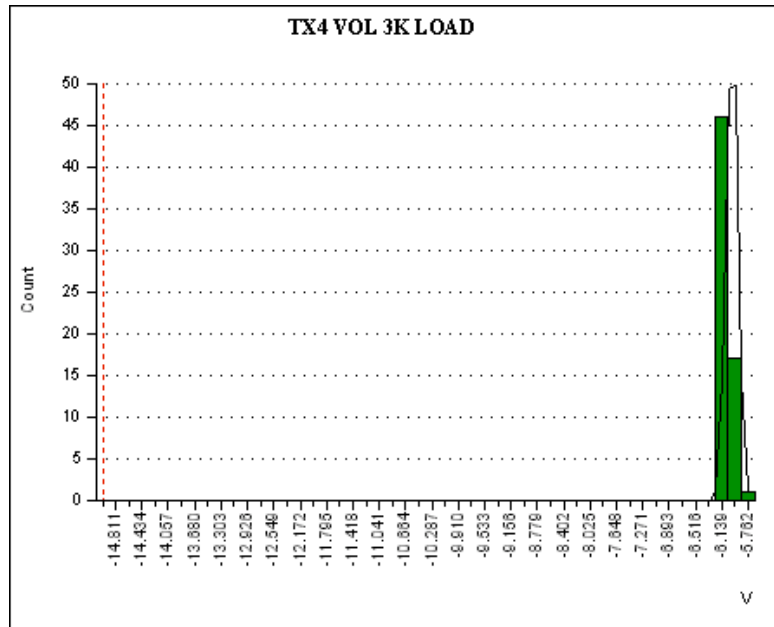
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.003, Test.Name=TX4 VOL 3K LOAD



Statistics: (V)

Max	-5.762	25%	-6.146	SpecHigh	N/A
Mean	-6.085	10%	-6.171	SpecLow	-15.000
Min	-6.212	N	64	PctWithinSpec	100.00
Range	449.612E-03	Cp	N/A	c	
StdDev	83.249E-03	Cpl	>4.0000	PctDefSpec	0
W	0.9090	Cpu	N/A	NWithinSpec	64
WpValue	0.0002	Cpk	>4.0000	NOutsideSpec	0
90%	-5.994	Skew	1.2801		
75%	-6.033	Kurtosis	2.4013		
Median	-6.107				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

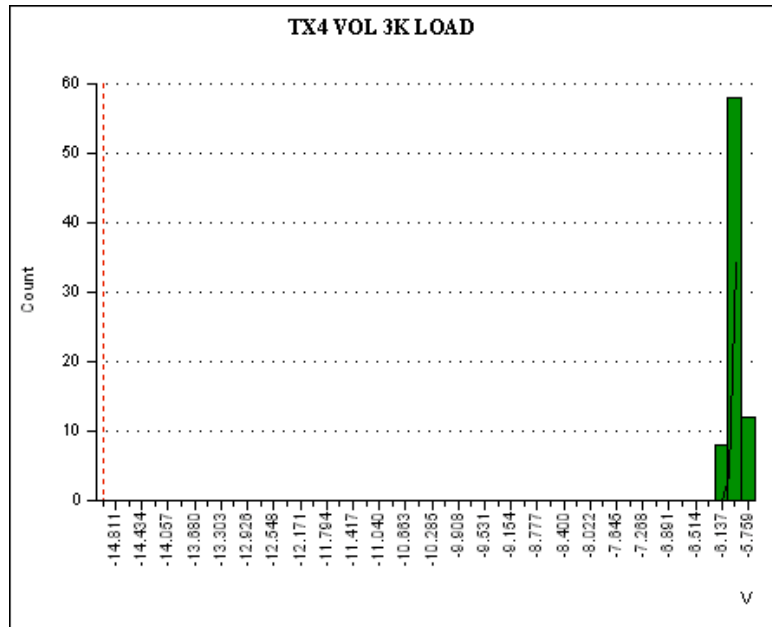
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.003, Test.Name=TX4 VOL 3K LOAD



Statistics: (V)

Max	-5.759	25%	-5.987	SpecHigh	N/A
Mean	-5.940	10%	-6.047	SpecLow	-15.000
Min	-6.110	N	78	PctWithinSpec	100.00
Range	350.827E-03	Cp	N/A	c	
StdDev	76.159E-03	Cpl	>4.0000	PctDefSpec	0
W	0.9894	Cpu	N/A	NWithinSpec	78
WpValue	0.7727	Cpk	>4.0000	NOutsideSpec	0
90%	-5.846	Skew	-0.1086		
75%	-5.894	Kurtosis	-0.1516		
Median	-5.935				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

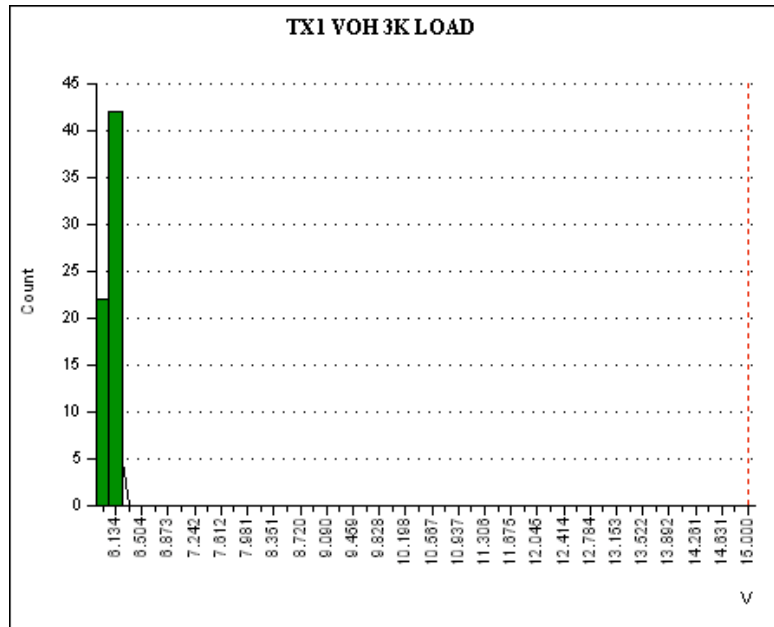
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.004, Test.Name=TX1 VOH 3K LOAD



Statistics: (V)

Max	6.198	25%	6.027	SpecHigh	15.000
Mean	6.079	10%	6.000	SpecLow	N/A
Min	5.950	N	64	PctWithinSpec	100.00
Range	248.307E-03	Cp	N/A	PctDefSpec	0
StdDev	59.760E-03	Cpl	N/A	NWithinSpec	64
W	0.9644	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0618	Cpk	>4.0000		
90%	6.155	Skew	-0.1232		
75%	6.119	Kurtosis	-0.8810		
Median	6.093				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

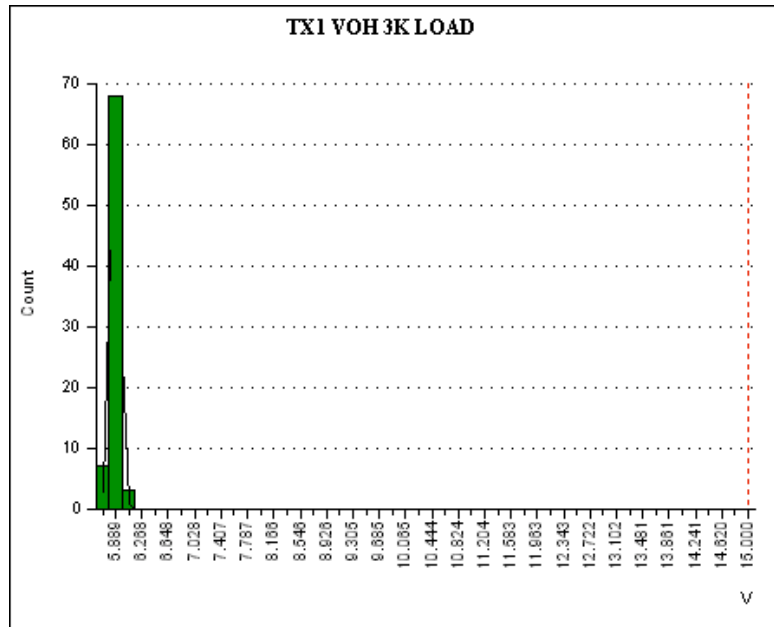
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=4.004, Test.Name=TX1 VOH 3K LOAD



Statistics: (V)

Max	6.027	25%	5.830	SpecHigh	15.000
Mean	5.872	10%	5.800	SpecLow	N/A
Min	5.699	N	78	PctWithinSpec	100.00
Range	327.749E-03	Cp	N/A	PctDefSpec	0
StdDev	65.816E-03	Cpl	N/A	NWithinSpec	78
W	0.9875	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.6479	Cpk	>4.0000		
90%	5.951	Skew	-0.2247		
75%	5.911	Kurtosis	0.2239		
Median	5.884				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

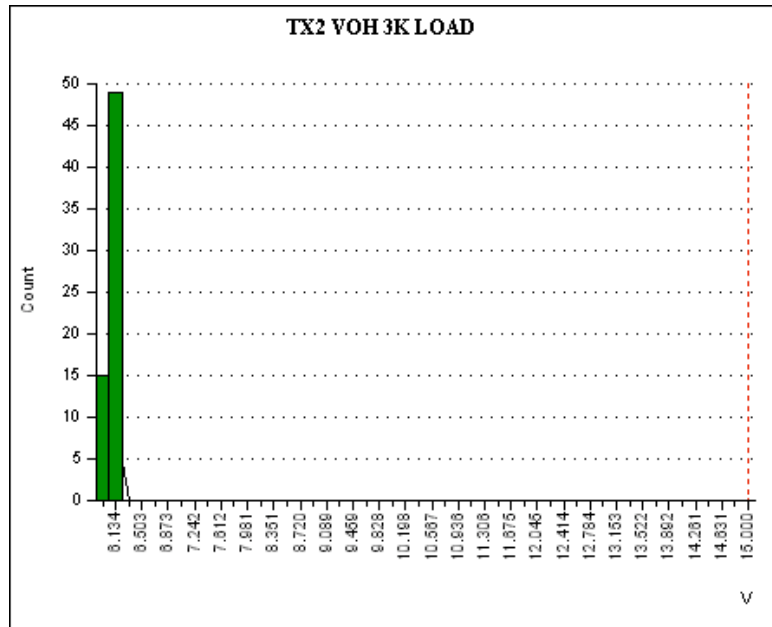
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.005, Test.Name=TX2 VOH 3K LOAD



Statistics: (V)

Max	6.196	25%	6.051	SpecHigh	15.000
Mean	6.085	10%	6.015	SpecLow	N/A
Min	5.949	N	64	PctWithinSpec	100.00
Range	246.256E-03	Cp	N/A	PctDefSpec	0
StdDev	56.460E-03	Cpl	N/A	NWithinSpec	64
W	0.9795	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.3657	Cpk	>4.0000		
90%	6.170	Skew	-0.0021		
75%	6.121	Kurtosis	-0.6191		
Median	6.082				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

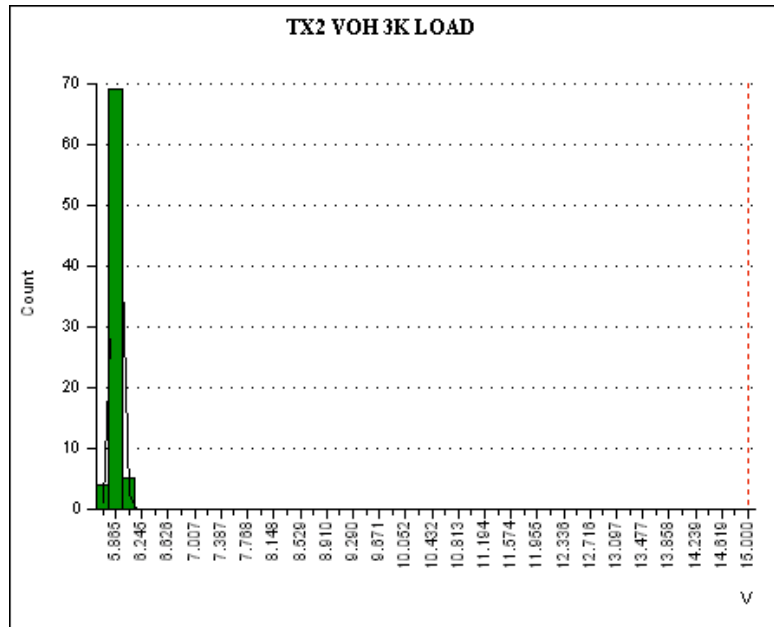
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.005, Test.Name=TX2 VOH 3K LOAD



Statistics: (V)

Max	6.013	25%	5.825	SpecHigh	15.000
Mean	5.868	10%	5.787	SpecLow	N/A
Min	5.674	N	78	PctWithinSpec	100.00
Range	338.487E-03	Cp	N/A	PctDefSpec	0
StdDev	65.919E-03	Cpl	N/A	NWithinSpec	78
W	0.9902	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.8193	Cpk	>4.0000		
90%	5.947	Skew	-0.3203		
75%	5.912	Kurtosis	0.3360		
Median	5.871				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

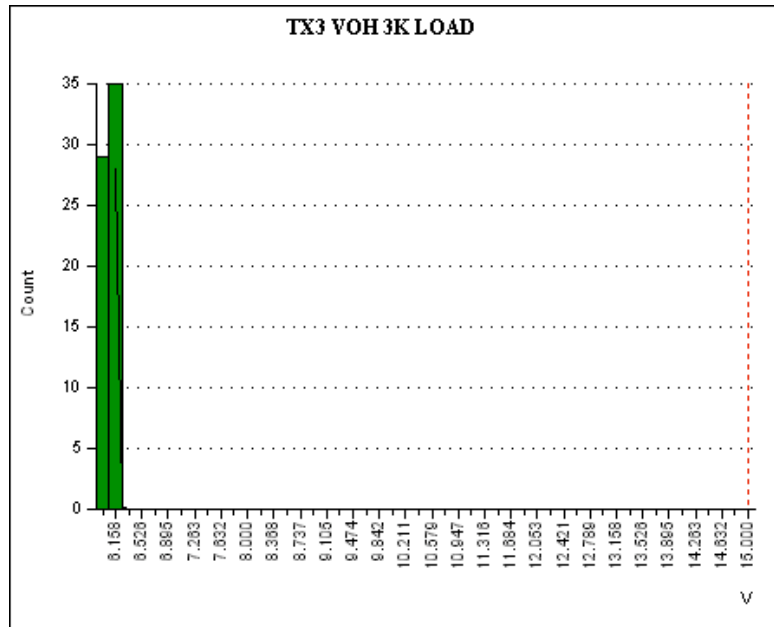
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.006, Test.Name=TX3 VOH 3K LOAD



Statistics: (V)

Max	6.166	25%	6.043	SpecHigh	15.000
Mean	6.078	10%	6.014	SpecLow	N/A
Min	5.974	N	64	PctWithinSpec	100.00
Range	192.786E-03	Cp	N/A	PctDefSpec	0
StdDev	48.611E-03	Cpl	N/A	NWithinSpec	64
W	0.9797	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.3743	Cpk	>4.0000		
90%	6.147	Skew	0.0073		
75%	6.118	Kurtosis	-0.7653		
Median	6.074				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

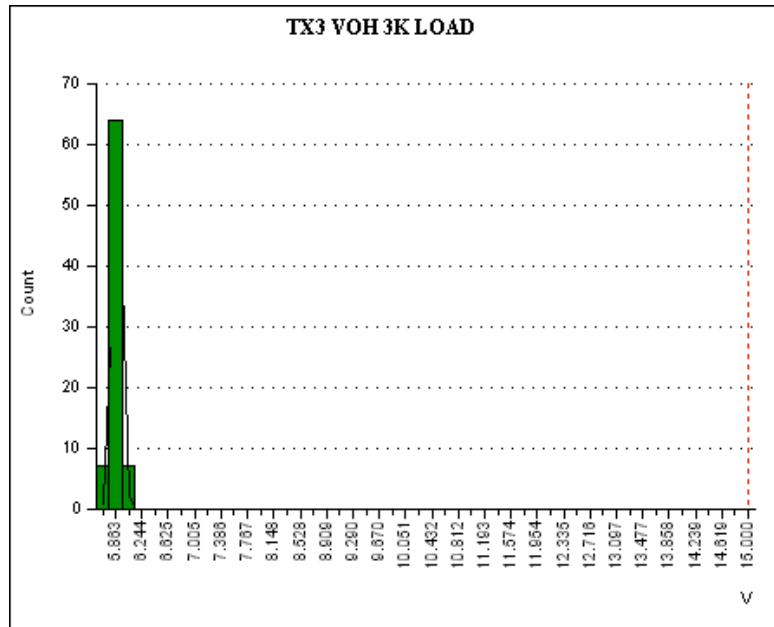
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.006, Test.Name=TX3 VOH 3K LOAD



Statistics: (V)

Max	6.018	25%	5.838	SpecHigh	15.000
Mean	5.867	10%	5.768	SpecLow	N/A
Min	5.673	N	78	PctWithinSpec	100.00
Range	344.810E-03	Cp	N/A	PctDefSpec	0
StdDev	64.207E-03	Cpl	N/A	NWithinSpec	78
W	0.9805	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.2753	Cpk	>4.0000		
90%	5.942	Skew	-0.3948		
75%	5.910	Kurtosis	0.7164		
Median	5.878				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

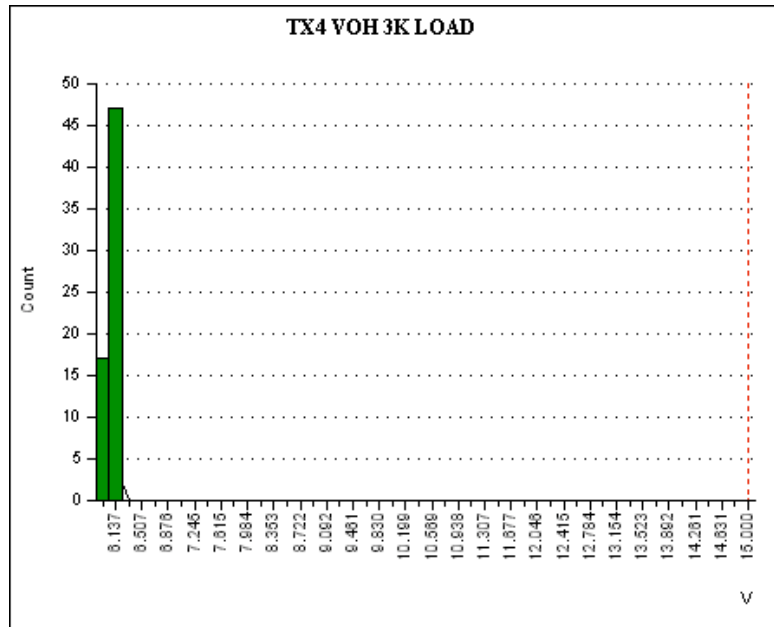
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.007, Test.Name=TX4 VOH 3K LOAD



Statistics: (V)

Max	6.213	25%	6.040	SpecHigh	15.000
Mean	6.080	10%	6.014	SpecLow	N/A
Min	5.953	N	64	PctWithinSpec	100.00
Range	260.278E-03	Cp	N/A	c	
StdDev	52.647E-03	Cpl	N/A	PctDefSpec	0
W	0.9959	Cpu	>4.0000	NWithinSpec	64
WpValue	0.9991	Cpk	>4.0000	NOutsideSpec	0
90%	6.146	Skew	-0.0145		
75%	6.114	Kurtosis	-0.1763		
Median	6.081				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

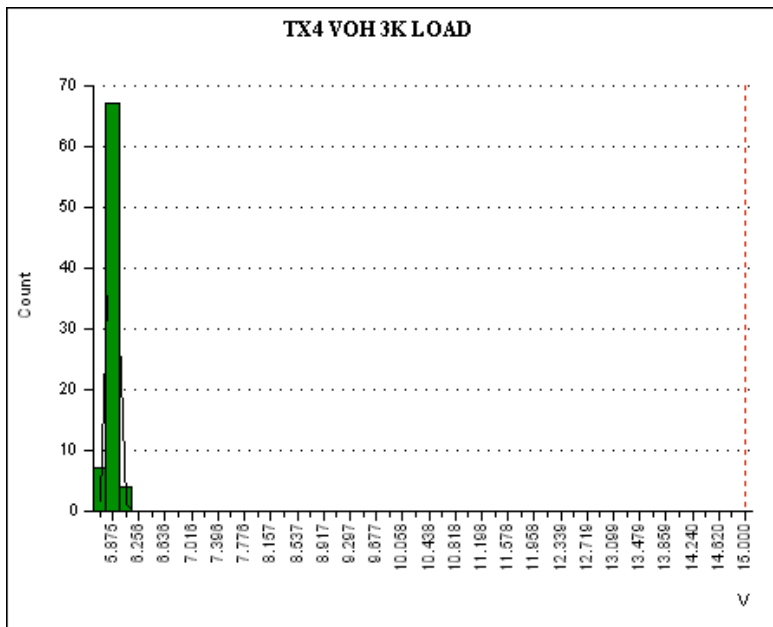
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.007, Test.Name=TX4 VOH 3K LOAD



Statistics: (V)

Max	6.013	25%	5.829	SpecHigh	15.000
Mean	5.867	10%	5.786	SpecLow	N/A
Min	5.685	N	78	PctWithinSpec	100.00
Range	327.746E-03	Cp	N/A	PctDefSpec	0
StdDev	64.213E-03	Cpl	N/A	NWithinSpec	78
W	0.9846	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.4673	Cpk	>4.0000		
90%	5.943	Skew	-0.4026		
75%	5.911	Kurtosis	0.3341		
Median	5.875				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

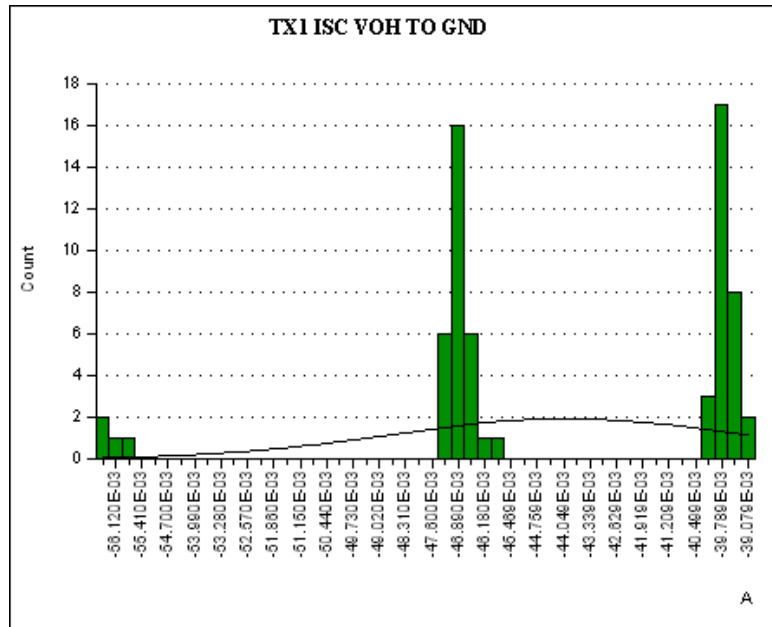
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=5.000, Test.Name=TX1 ISC VOH TO GND



Statistics: (A)

Max	-39.079E-03	25%	-46.921E-03	SpecHigh	N/A
Mean	-44.078E-03	10%	-47.212E-03	SpecLow	N/A
Min	-56.475E-03	N	64	PctWithinSpec	N/A
Range	17.396E-03	Cp	N/A	PctDefSpec	N/A
StdDev	4.698E-03	Cpl	N/A	NWithinSpec	N/A
W	0.7773	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	-39.520E-03	Skew	-0.8151		
75%	-39.762E-03	Kurtosis	0.3686		
Median	-46.381E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

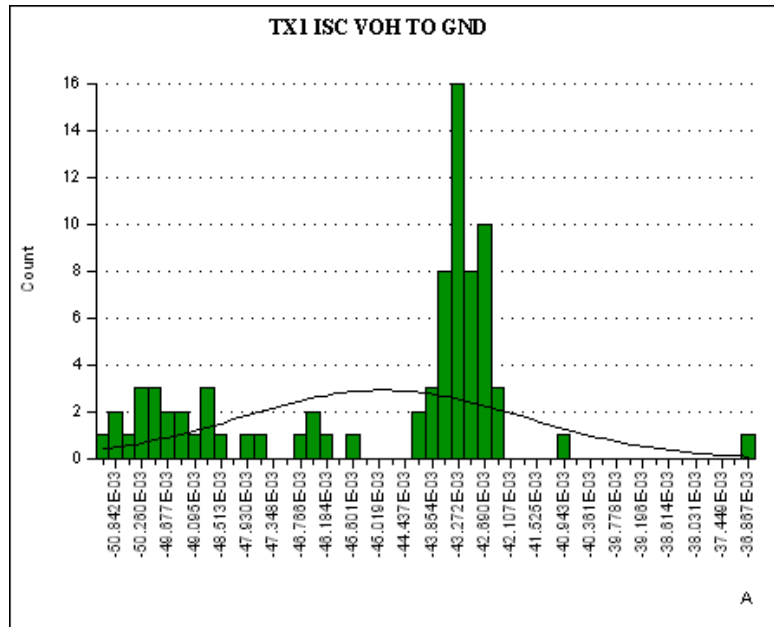
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=5.000, Test.Name=TX1 ISC VOH TO GND



Statistics: (A)

Max	-36.867E-03	25%	-47.854E-03	SpecHigh	N/A
Mean	-44.997E-03	10%	-50.107E-03	SpecLow	N/A
Min	-51.133E-03	N	78	PctWithinSpec	N/A
Range	14.266E-03	Cp	N/A	PctDefSpec	N/A
StdDev	3.088E-03	Cpl	N/A	NWithinSpec	N/A
W	0.8138	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	-42.668E-03	Skew	-0.6317		
75%	-42.991E-03	Kurtosis	-0.4520		
Median	-43.429E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

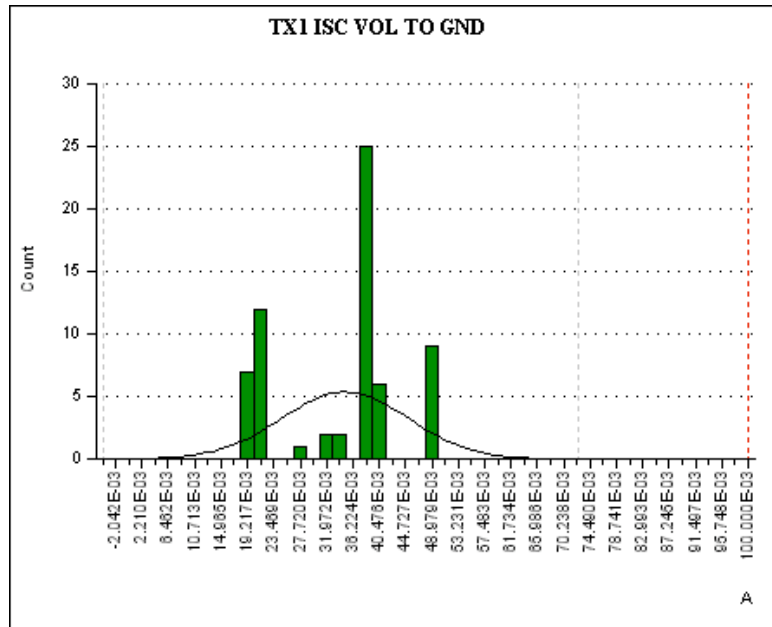
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=5.004, Test.Name=TX1 ISC VOL TO GND



Statistics: (A)

Max	50.032E-03	25%	21.460E-03	SpecHigh	100.000E-03
Mean	34.556E-03	10%	20.254E-03	SpecLow	N/A
Min	19.664E-03	N	64	PctWithinSpec	100.00
Range	30.368E-03	Cp	N/A	PctDefSpec	0
StdDev	10.135E-03	Cpl	N/A	NWithinSpec	64
W	0.8342	Cpu	2.1525	NOutsideSpec	0
WpValue	0.0000	Cpk	2.1525		
90%	49.656E-03	Skew	-0.2797		
75%	39.148E-03	Kurtosis	-1.1245		
Median	38.810E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

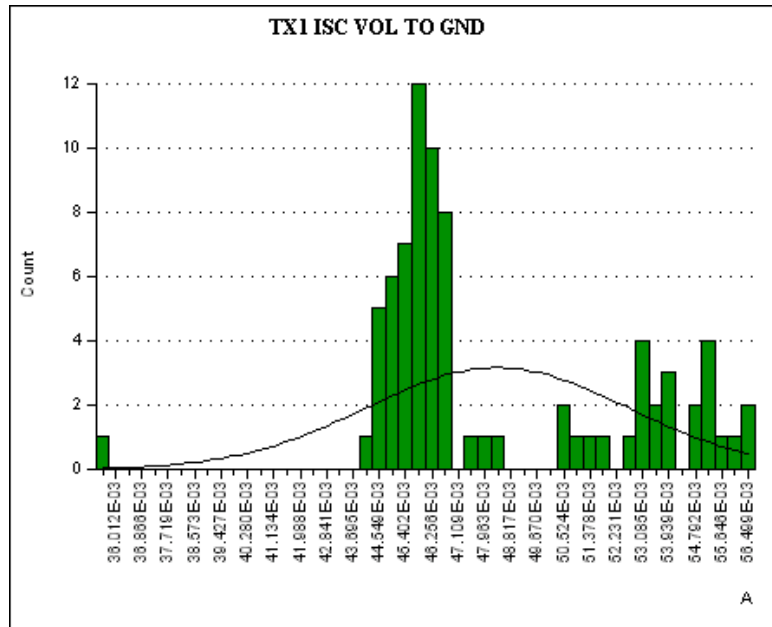
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
72.653E-03	-4.168E-03	100.00	0	64	0

Plot limits applied

NOutsidePlot

0

Test.Number=5.001, Test.Name=TX1 ISC VOL TO GND



Statistics: (A)

Max	56.499E-03	25%	45.491E-03	SpecHigh	N/A
Mean	48.241E-03	10%	44.844E-03	SpecLow	N/A
Min	35.585E-03	N	78	PctWithinSpec	N/A
Range	20.914E-03	Cp	N/A	PctDefSpec	N/A
StdDev	4.189E-03	Cpl	N/A	NWithinSpec	N/A
W	0.8354	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	55.116E-03	Skew	0.4514		
75%	52.844E-03	Kurtosis	-0.1014		
Median	46.193E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

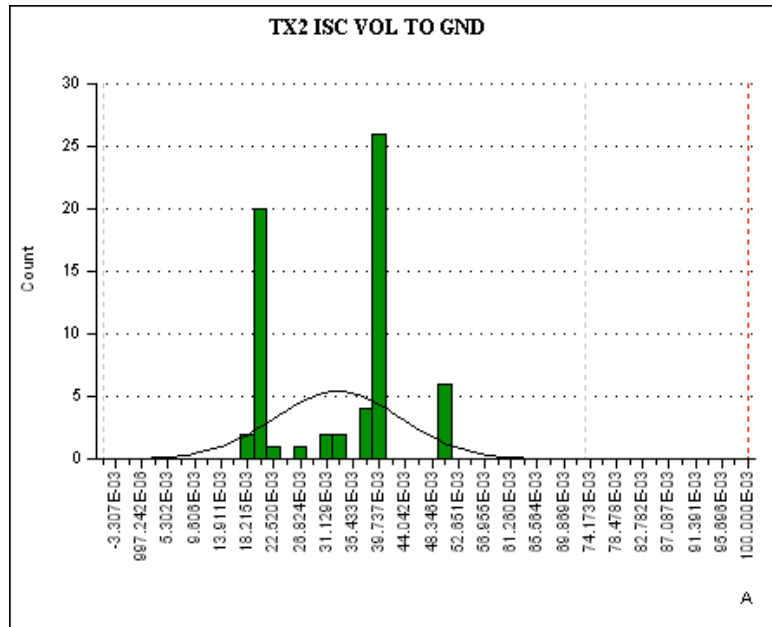
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=5.005, Test.Name=TX2 ISC VOL TO GND



Statistics: (A)

Max	49.941E-03	25%	20.242E-03	SpecHigh	100.000E-03
Mean	32.569E-03	10%	19.859E-03	SpecLow	N/A
Min	18.987E-03	N	64	PctWithinSpec	100.00
Range	30.954E-03	Cp	N/A	PctDefSpec	0
StdDev	10.207E-03	Cpl	N/A	NWithinSpec	64
W	0.8207	Cpu	2.2021	NOutsideSpec	0
WpValue	0.0000	Cpk	2.2021		
90%	39.885E-03	Skew	-0.1078		
75%	38.979E-03	Kurtosis	-1.3507		
Median	38.666E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

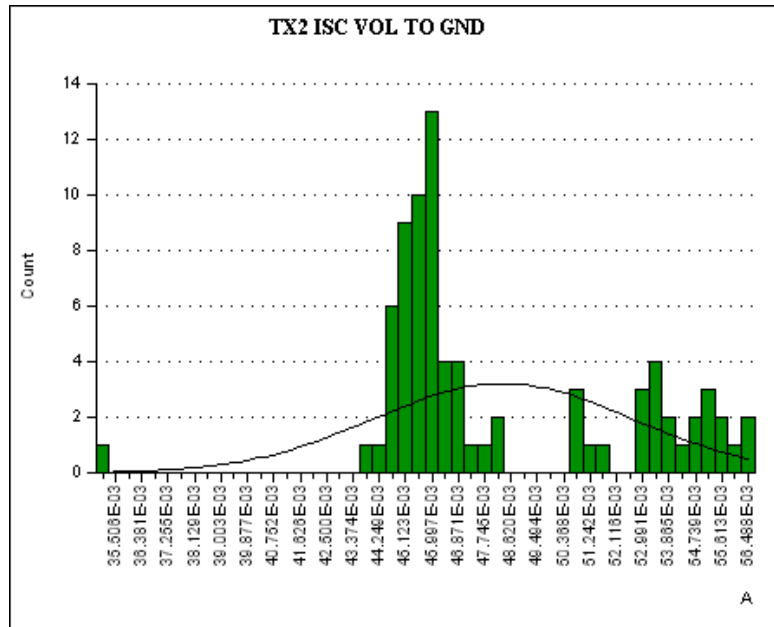
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
73.209E-03	-5.459E-03	100.00	0	64	0

Plot limits applied

NOutsidePlot

0

Test.Number=5.002, Test.Name=TX2 ISC VOL TO GND



Statistics: (A)

Max	56.488E-03	25%	45.406E-03	SpecHigh	N/A
Mean	48.219E-03	10%	44.762E-03	SpecLow	N/A
Min	35.069E-03	N	78	PctWithinSpec	N/A
Range	21.418E-03	Cp	N/A	c	
StdDev	4.234E-03	Cpl	N/A	PctDefSpec	N/A
W	0.8398	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	55.083E-03	Skew	0.4025		
75%	52.801E-03	Kurtosis	-0.0002		
Median	46.141E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

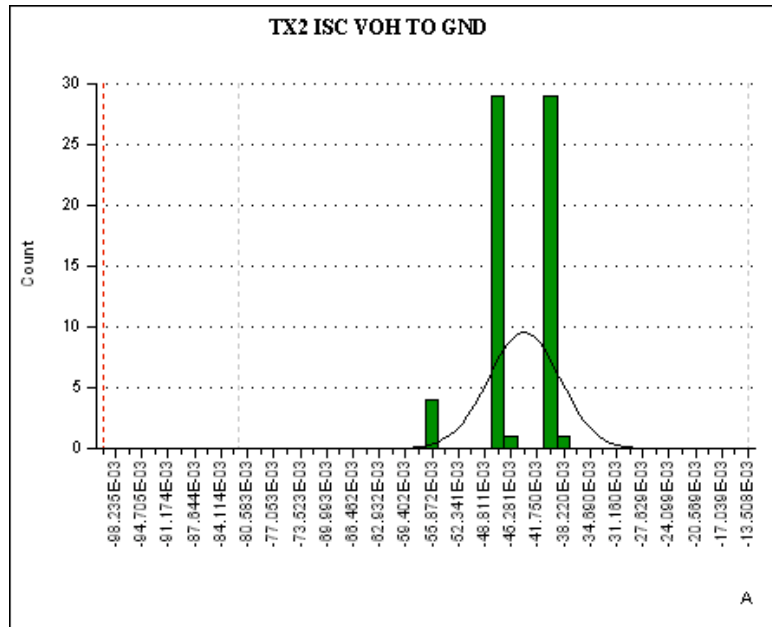
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=5.001, Test.Name=TX2 ISC VOH TO GND



Statistics: (A)

Max	-39.070E-03	25%	-46.972E-03	SpecHigh	N/A
Mean	-44.122E-03	10%	-47.279E-03	SpecLow	-100.000E-03
Min	-56.585E-03	N	64	PctWithinSpec	100.00
Range	17.515E-03	Cp	N/A	PctDefSpec	0
StdDev	4.698E-03	Cpl	3.9650	NWithinSpec	64
W	0.7799	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	3.9650		
90%	-39.567E-03	Skew	-0.8088		
75%	-39.829E-03	Kurtosis	0.3516		
Median	-46.347E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

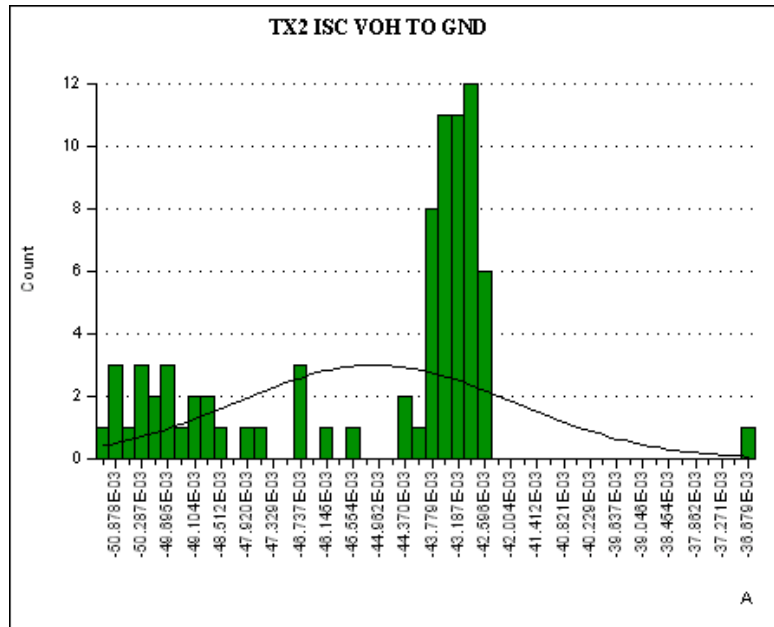
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
-13.508E-03	-81.745E-03	100.00	0	64	0

Plot limits applied

NOutsidePlot

0

Test.Number=5.003, Test.Name=TX2 ISC VOH TO GND



Statistics: (A)

Max	-36.679E-03	25%	-48.023E-03	SpecHigh	N/A
Mean	-45.113E-03	10%	-50.194E-03	SpecLow	N/A
Min	-51.174E-03	N	78	PctWithinSpec	N/A
Range	14.495E-03	Cp	N/A	PctDefSpec	N/A
StdDev	3.063E-03	Cpl	N/A	NWithinSpec	N/A
W	0.8082	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	-42.763E-03	Skew	-0.6024		
75%	-43.066E-03	Kurtosis	-0.3576		
Median	-43.555E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

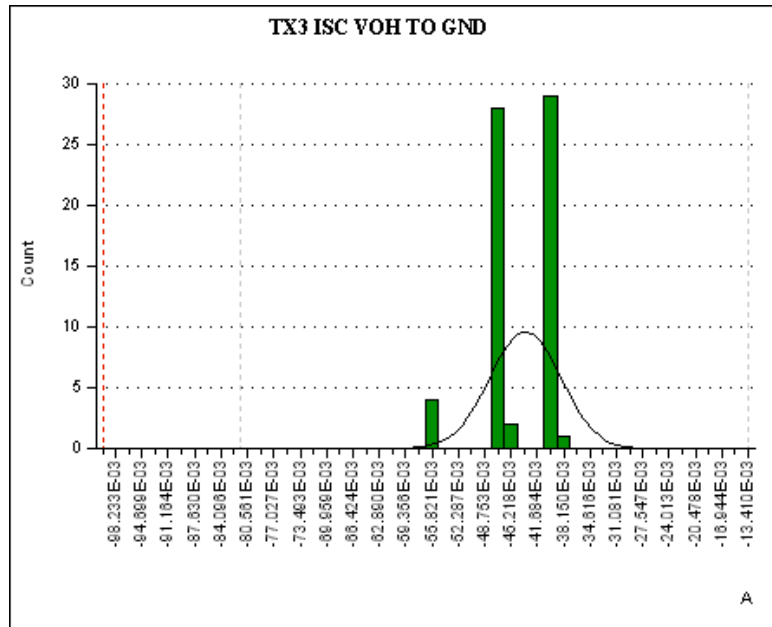
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=5.002, Test.Name=TX3 ISC VOH TO GND



Statistics: (A)

Max	-38.951E-03	25%	-46.795E-03	SpecHigh	N/A
Mean	-43.934E-03	10%	-47.043E-03	SpecLow	-100.000E-03
Min	-56.246E-03	N	64	PctWithinSpec	100.00
Range	17.295E-03	Cp	N/A	PctDefSpec	0
StdDev	4.678E-03	Cpl	3.9952	NWithinSpec	64
W	0.7759	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	3.9952		
90%	-39.383E-03	Skew	-0.8186		
75%	-39.630E-03	Kurtosis	0.3778		
Median	-46.219E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

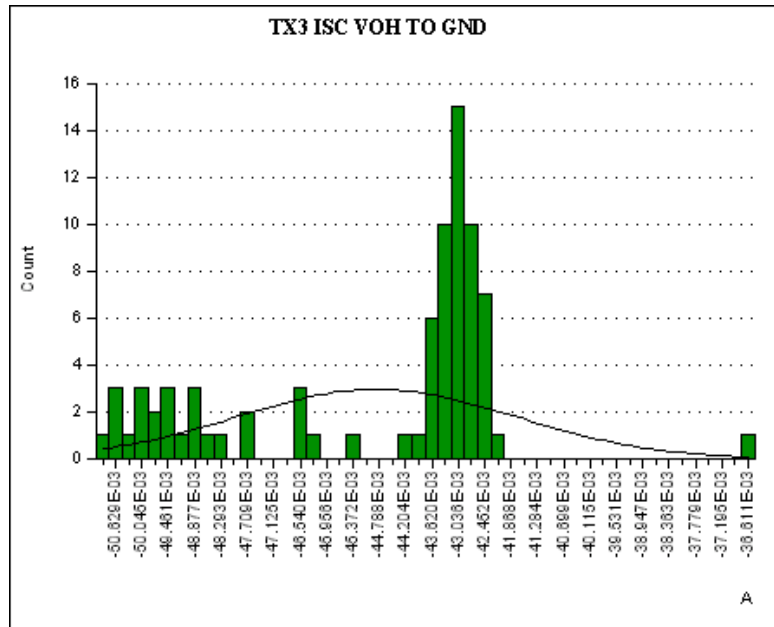
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
-13.410E-03	-81.501E-03	100.00	0	64	0

Plot limits applied

NOutsidePlot

0

Test.Number=5.004, Test.Name=TX3 ISC VOH TO GND



Statistics: (A)

Max	-36.611E-03	25%	-47.797E-03	SpecHigh	N/A
Mean	-44.902E-03	10%	-49.899E-03	SpecLow	N/A
Min	-50.921E-03	N	78	PctWithinSpec	N/A
Range	14.311E-03	Cp	N/A	PctDefSpec	N/A
StdDev	3.056E-03	Cpl	N/A	NWithinSpec	N/A
W	0.8044	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	-42.578E-03	Skew	-0.6179		
75%	-42.935E-03	Kurtosis	-0.4000		
Median	-43.298E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

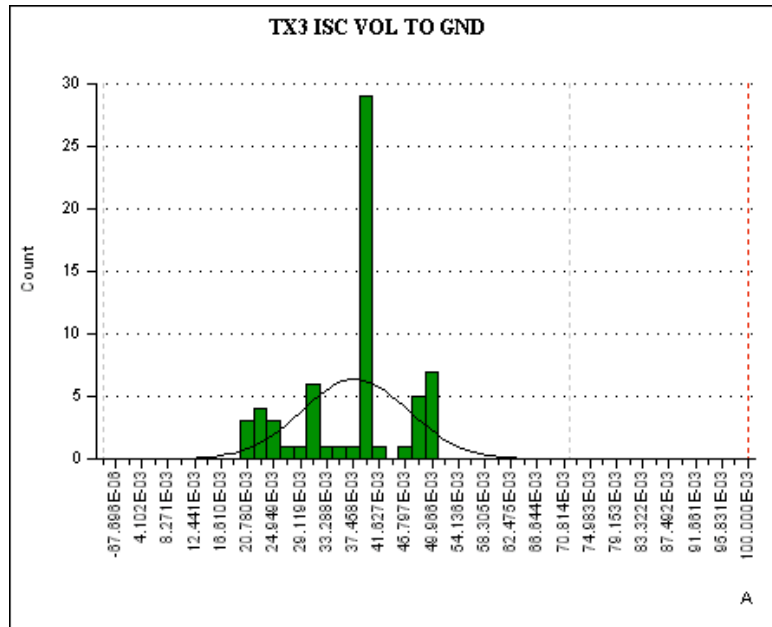
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=5.006, Test.Name=TX3 ISC VOL TO GND



Statistics: (A)

Max	49.856E-03	25%	31.653E-03	SpecHigh	100.000E-03
Mean	37.378E-03	10%	23.192E-03	SpecLow	N/A
Min	20.557E-03	N	64	PctWithinSpec	100.00
Range	29.299E-03	Cp	N/A	PctDefSpec	0
StdDev	8.340E-03	Cpl	N/A	NWithinSpec	64
W	0.8987	Cpu	2.5029	NOutsideSpec	0
WpValue	0.0001	Cpk	2.5029		
90%	49.117E-03	Skew	-0.3956		
75%	39.782E-03	Kurtosis	-0.4888		
Median	38.863E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

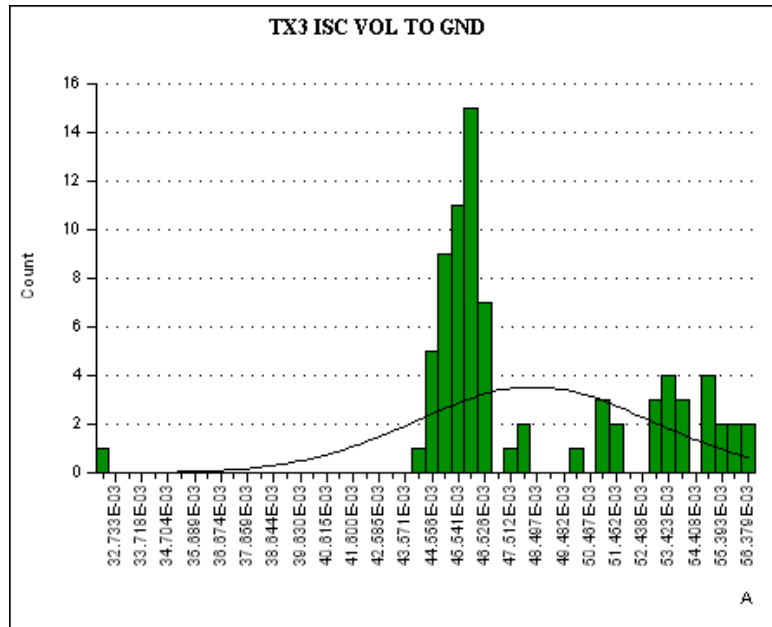
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
71.642E-03	-2.152E-03	100.00	0	64	0

Plot limits applied

NOutsidePlot

0

Test.Number=5.005, Test.Name=TX3 ISC VOL TO GND



Statistics: (A)

Max	56.379E-03	25%	45.519E-03	SpecHigh	N/A
Mean	48.201E-03	10%	44.810E-03	SpecLow	N/A
Min	32.240E-03	N	78	PctWithinSpec	N/A
Range	24.138E-03	Cp	N/A	c	
StdDev	4.338E-03	Cpl	N/A	PctDefSpec	N/A
W	0.8344	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	54.883E-03	Skew	0.0682		
75%	52.770E-03	Kurtosis	1.0483		
Median	46.101E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

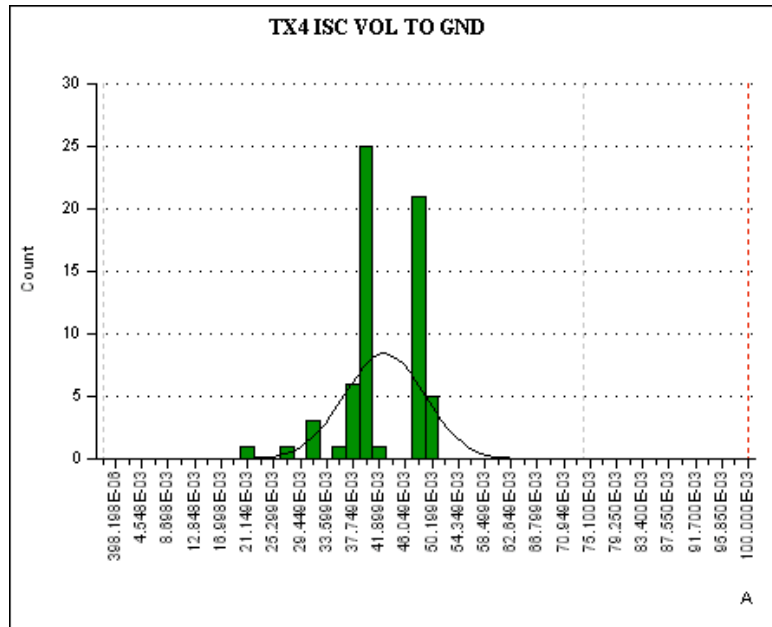
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=5.007, Test.Name=TX4 ISC VOL TO GND



Statistics: (A)

Max	49.350E-03	25%	38.853E-03	SpecHigh	100.000E-03
Mean	42.206E-03	10%	38.088E-03	SpecLow	N/A
Min	21.007E-03	N	64	PctWithinSpec	100.00
Range	28.343E-03	Cp	N/A	PctDefSpec	0
StdDev	6.291E-03	Cpl	N/A	NWithinSpec	64
W	0.8244	Cpu	3.0624	NOutsideSpec	0
WpValue	0.0000	Cpk	3.0624		
90%	49.134E-03	Skew	-0.6570		
75%	48.742E-03	Kurtosis	0.6768		
Median	39.351E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

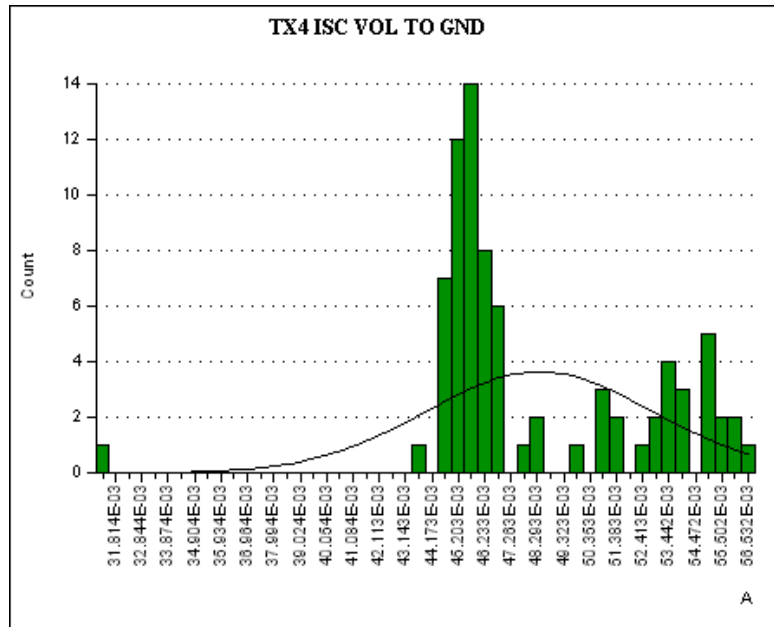
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
73.968E-03	-1.677E-03	100.00	0	64	0

Plot limits applied

NOutsidePlot

0

Test.Number=5.006, Test.Name=TX4 ISC VOL TO GND



Statistics: (A)

Max	56.532E-03	25%	45.394E-03	SpecHigh	N/A
Mean	48.204E-03	10%	44.716E-03	SpecLow	N/A
Min	31.299E-03	N	78	PctWithinSpec	N/A
Range	25.233E-03	Cp	N/A	PctDefSpec	N/A
StdDev	4.406E-03	Cpl	N/A	NWithinSpec	N/A
W	0.8329	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	55.132E-03	Skew	-0.0372		
75%	52.621E-03	Kurtosis	1.4659		
Median	46.214E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

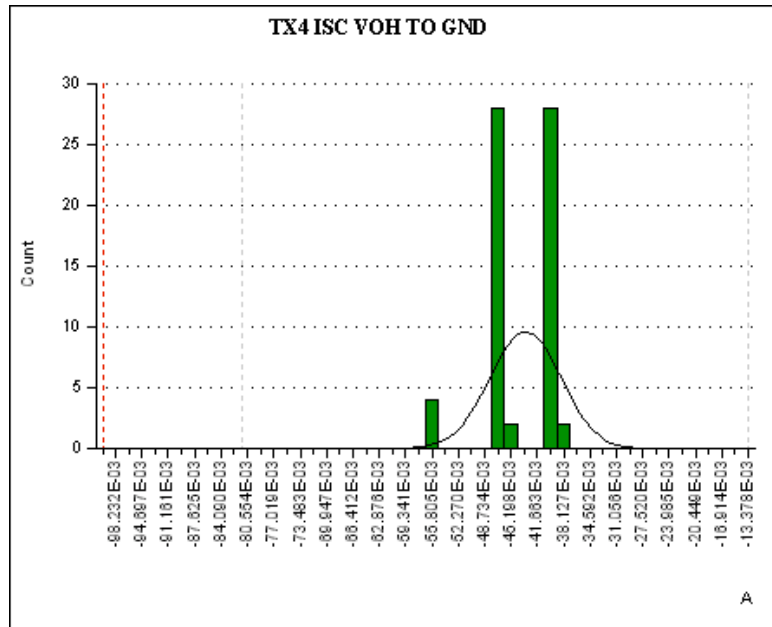
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=5.003, Test.Name=TX4 ISC VOH TO GND



Statistics: (A)

Max	-38.896E-03	25%	-46.735E-03	SpecHigh	N/A
Mean	-43.858E-03	10%	-46.962E-03	SpecLow	-100.000E-03
Min	-56.242E-03	N	64	PctWithinSpec	100.00
Range	17.345E-03	Cp	N/A	PctDefSpec	0
StdDev	4.686E-03	Cpl	3.9938	NWithinSpec	64
W	0.7778	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	3.9938		
90%	-39.358E-03	Skew	-0.8231		
75%	-39.542E-03	Kurtosis	0.3920		
Median	-46.076E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

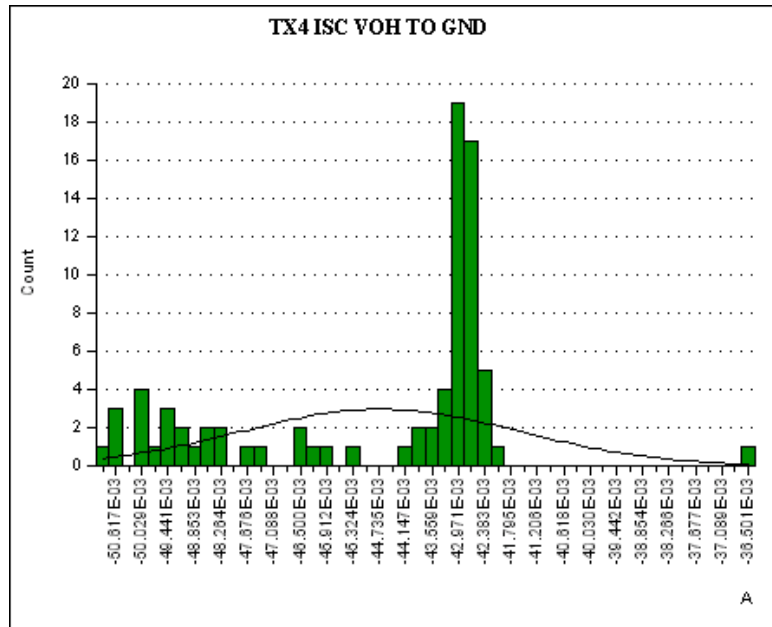
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
-13.378E-03	-81.390E-03	100.00	0	64	0

Plot limits applied

NOutsidePlot

0

Test.Number=5.007, Test.Name=TX4 ISC VOH TO GND



Statistics: (A)

Max	-36.501E-03	25%	-47.809E-03	SpecHigh	N/A
Mean	-44.763E-03	10%	-49.897E-03	SpecLow	N/A
Min	-50.911E-03	N	78	PctWithinSpec	N/A
Range	14.410E-03	Cp	N/A	c	
StdDev	3.079E-03	Cpl	N/A	PctDefSpec	N/A
W	0.7958	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	-42.532E-03	Skew	-0.6356		
75%	-42.739E-03	Kurtosis	-0.4202		
Median	-43.069E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

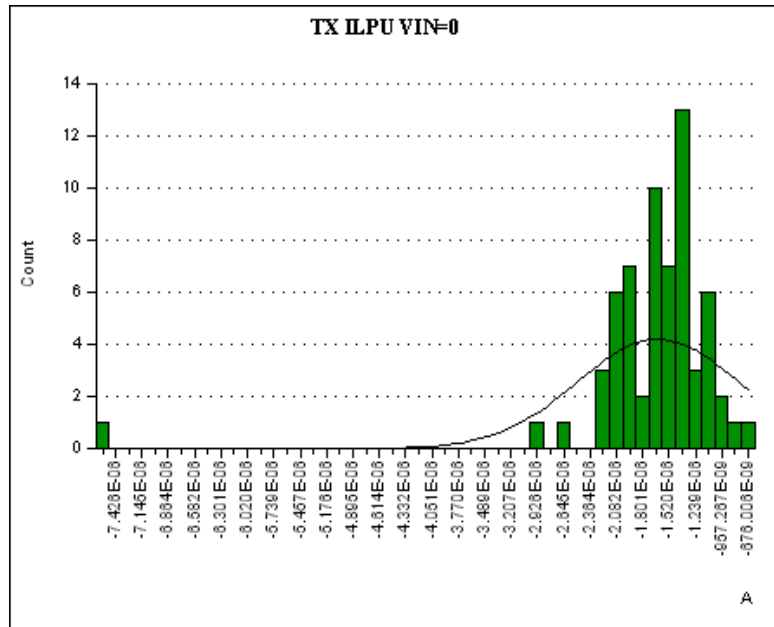
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=6.000, Test.Name=TX ILPU VIN=0



Statistics: (A)

Max	-676.006E-09	25%	-1.945E-06	SpecHigh	N/A
Mean	-1.697E-06	10%	-2.136E-06	SpecLow	N/A
Min	-7.567E-06	N	64	PctWithinSpec	N/A
Range	6.891E-06	Cp	N/A	c	
StdDev	853.948E-09	Cpl	N/A	PctDefSpec	N/A
W	0.5424	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	-1.096E-06	Skew	-5.2928		
75%	-1.330E-06	Kurtosis	36.0471		
Median	-1.571E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

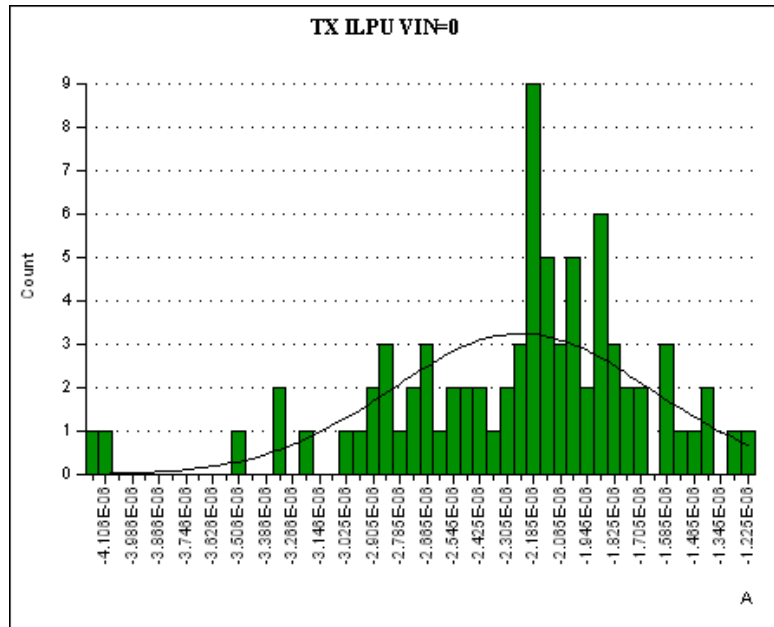
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=6.000, Test.Name=TX ILPU VIN=0



Statistics: (A)

Max	-1.225E-06	25%	-2.615E-06	SpecHigh	N/A
Mean	-2.262E-06	10%	-2.948E-06	SpecLow	N/A
Min	-4.166E-06	N	78	PctWithinSpec	N/A
Range	2.941E-06	Cp	N/A	c	
StdDev	574.467E-09	Cpl	N/A	PctDefSpec	N/A
W	0.9423	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0015	Cpk	N/A	NOutsideSpec	N/A
90%	-1.562E-06	Skew	-0.9912		
75%	-1.890E-06	Kurtosis	1.5900		
Median	-2.179E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

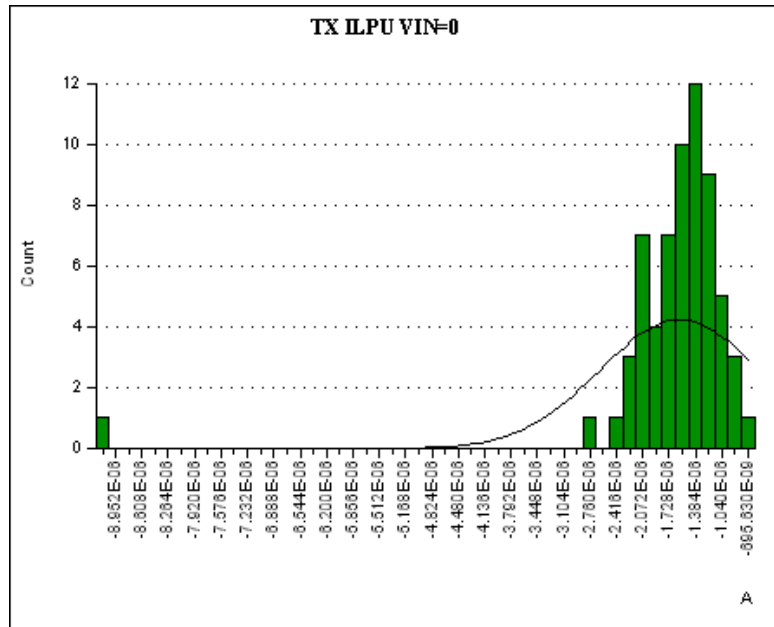
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=6.001, Test.Name=TX ILPU VIN=0



Statistics: (A)

Max	-695.630E-09	25%	-1.827E-06	SpecHigh	N/A
Mean	-1.667E-06	10%	-2.148E-06	SpecLow	N/A
Min	-9.124E-06	N	64	PctWithinSpec	N/A
Range	8.429E-06	Cp	N/A	c	
StdDev	1.036E-06	Cpl	N/A	PctDefSpec	N/A
W	0.4523	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	-1.011E-06	Skew	-6.0902		
75%	-1.266E-06	Kurtosis	43.8840		
Median	-1.515E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

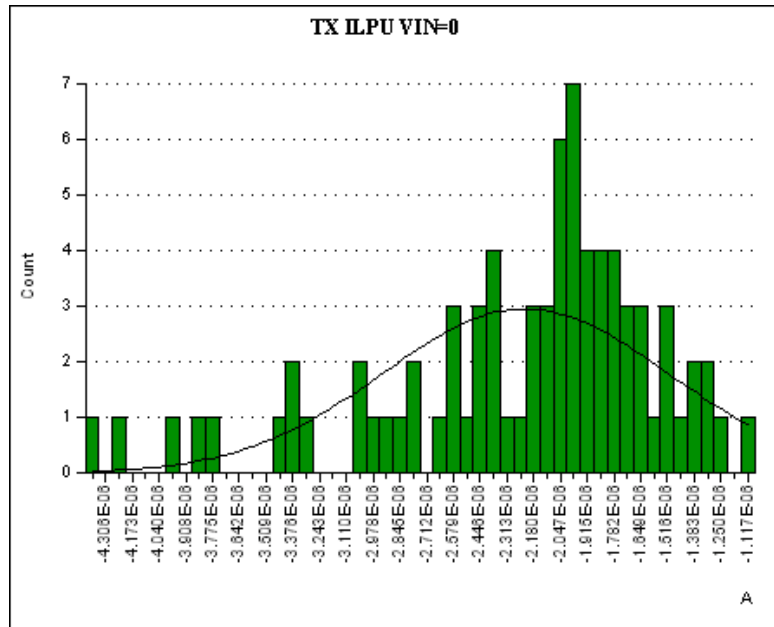
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=6.001, Test.Name=TX ILPU VIN=0



Statistics: (A)

Max	-1.117E-06	25%	-2.554E-06	SpecHigh	N/A
Mean	-2.244E-06	10%	-3.343E-06	SpecLow	N/A
Min	-4.373E-06	N	78	PctWithinSpec	N/A
Range	3.255E-06	Cp	N/A	c	
StdDev	700.212E-09	Cpl	N/A	PctDefSpec	N/A
W	0.9167	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0001	Cpk	N/A	NOutsideSpec	N/A
90%	-1.488E-06	Skew	-1.1072		
75%	-1.805E-06	Kurtosis	1.0306		
Median	-2.044E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

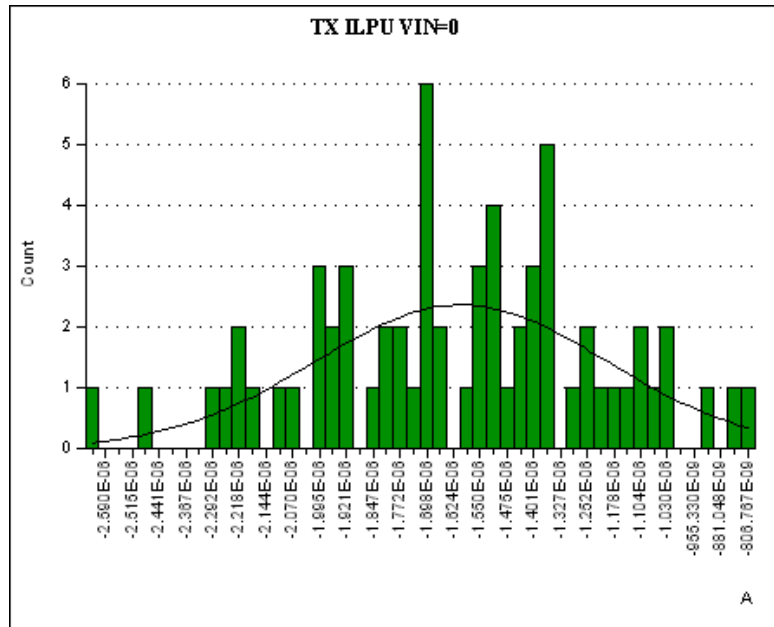
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=6.002, Test.Name=TX ILPU VIN=0



Statistics: (A)

Max	-806.767E-09	25%	-1.919E-06	SpecHigh	N/A
Mean	-1.613E-06	10%	-2.171E-06	SpecLow	N/A
Min	-2.627E-06	N	64	PctWithinSpec	N/A
Range	1.820E-06	Cp	N/A	PctDefSpec	N/A
StdDev	401.381E-09	Cpl	N/A	NWithinSpec	N/A
W	0.9894	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.8605	Cpk	N/A		
90%	-1.088E-06	Skew	-0.2248		
75%	-1.358E-06	Kurtosis	-0.2893		
Median	-1.564E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

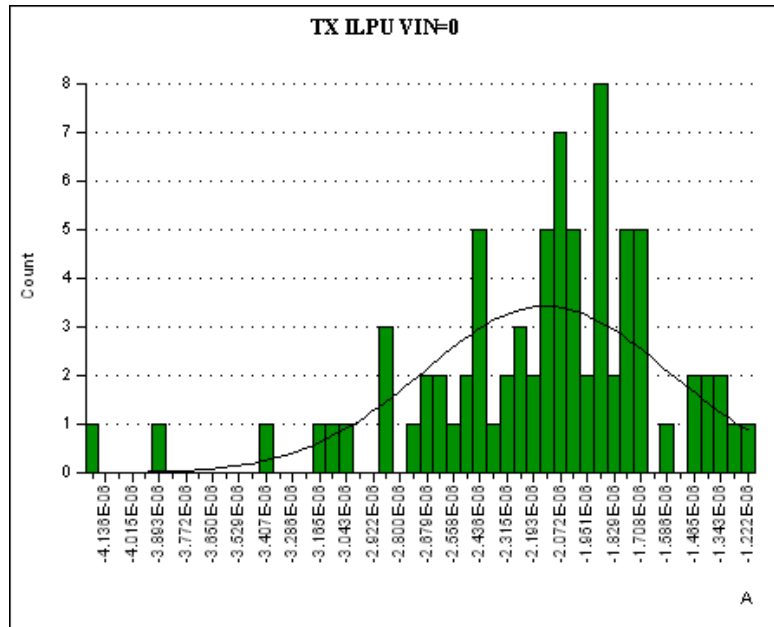
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=6.002, Test.Name=TX ILPU VIN=0



Statistics: (A)

Max	-1.222E-06	25%	-2.458E-06	SpecHigh	N/A
Mean	-2.160E-06	10%	-2.875E-06	SpecLow	N/A
Min	-4.197E-06	N	78	PctWithinSpec	N/A
Range	2.975E-06	Cp	N/A	c	
StdDev	550.611E-09	Cpl	N/A	PctDefSpec	N/A
W	0.9275	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0003	Cpk	N/A	NOutsideSpec	N/A
90%	-1.453E-06	Skew	-1.1868		
75%	-1.816E-06	Kurtosis	2.4448		
Median	-2.082E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

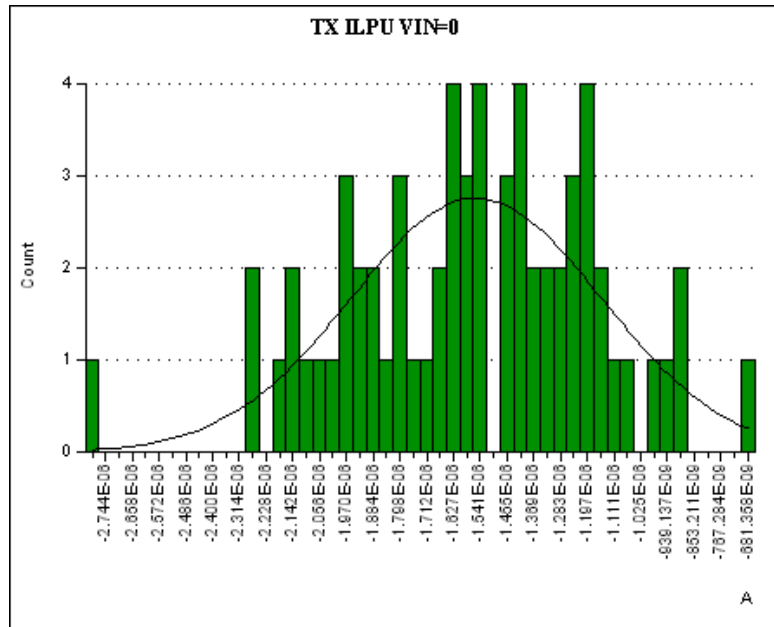
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=6.003, Test.Name=TX ILPU VIN=0



Statistics: (A)

Max	-681.358E-09	25%	-1.865E-06	SpecHigh	N/A
Mean	-1.568E-06	10%	-2.081E-06	SpecLow	N/A
Min	-2.787E-06	N	64	PctWithinSpec	N/A
Range	2.105E-06	Cp	N/A	c	
StdDev	397.430E-09	Cpl	N/A	PctDefSpec	N/A
W	0.9870	Cpu	N/A	NWithinSpec	N/A
WpValue	0.7379	Cpk	N/A	NOutsideSpec	N/A
90%	-1.097E-06	Skew	-0.3563		
75%	-1.261E-06	Kurtosis	0.2801		
Median	-1.560E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

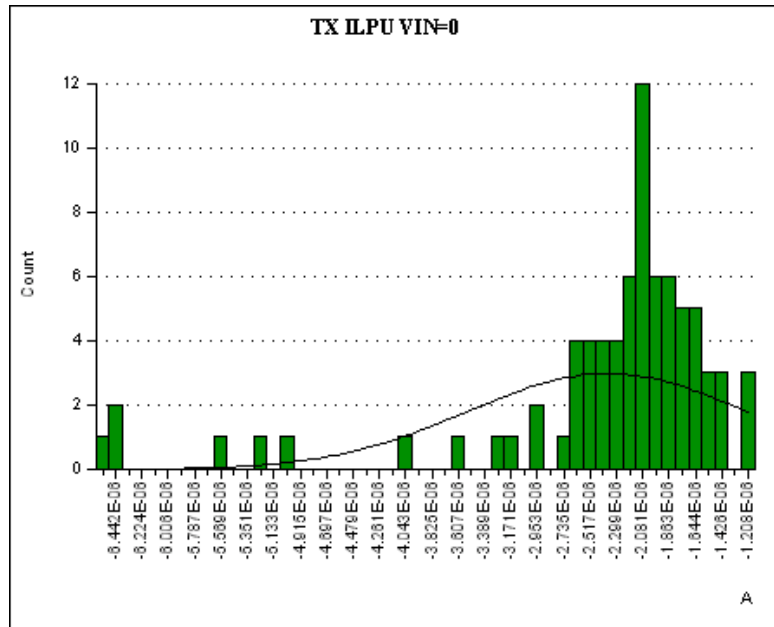
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=6.003, Test.Name=TX ILPU VIN=0



Statistics: (A)

Max	-1.208E-06	25%	-2.479E-06	SpecHigh	N/A
Mean	-2.414E-06	10%	-3.585E-06	SpecLow	N/A
Min	-6.551E-06	N	78	PctWithinSpec	N/A
Range	5.342E-06	Cp	N/A	c	
StdDev	1.137E-06	Cpl	N/A	PctDefSpec	N/A
W	0.6940	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	-1.583E-06	Skew	-2.4126		
75%	-1.870E-06	Kurtosis	5.7334		
Median	-2.089E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

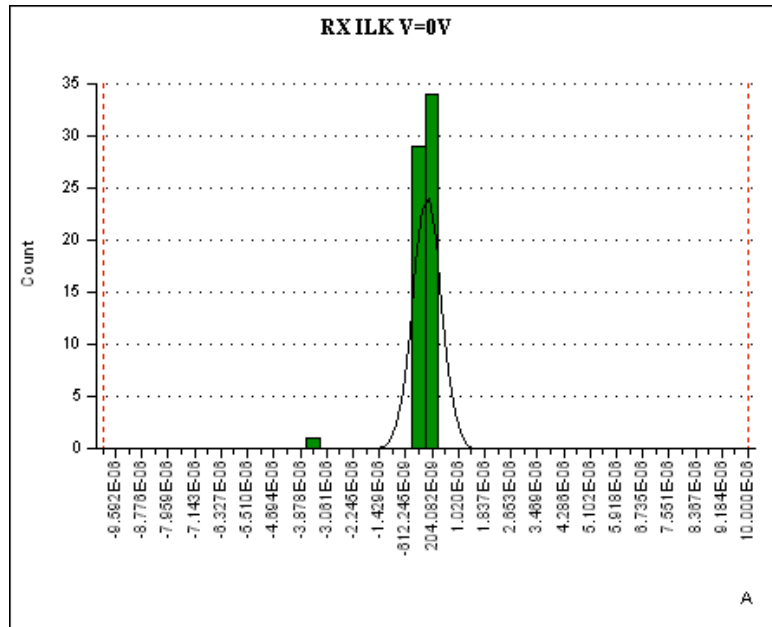
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=7.000, Test.Name=RX ILK V=0V



Statistics: (A)

Max	37.354E-09	25%	-14.039E-09	SpecHigh	10.000E-06
Mean	-61.791E-09	10%	-20.559E-09	SpecLow	-10.000E-06
Min	-3.445E-06	N	64	PctWithinSpec	100.00
Range	3.482E-06	Cp	>4.0000	c	
StdDev	431.170E-09	Cpl	>4.0000	PctDefSpec	0
W	0.1405	Cpu	>4.0000	NWithinSpec	64
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	9.559E-09	Skew	-7.9118		
75%	5.357E-09	Kurtosis	63.0134		
Median	1.045E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

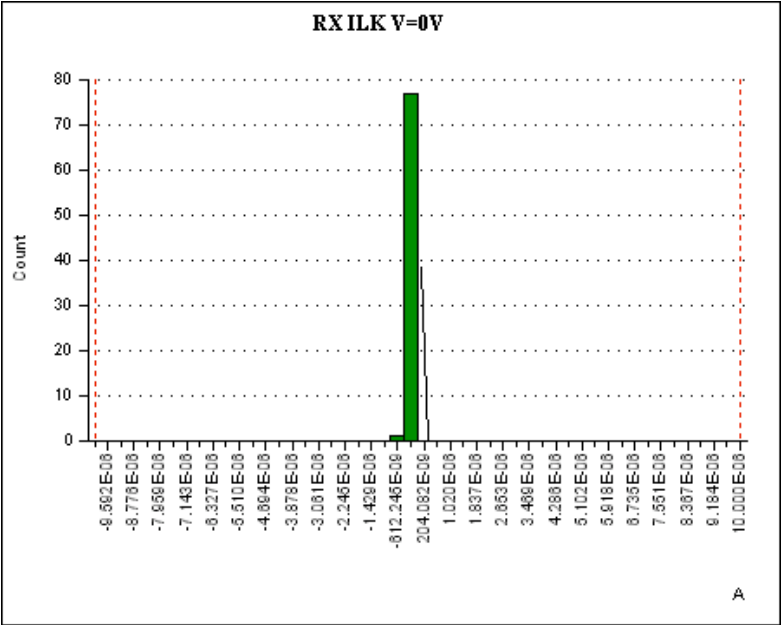
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.000, Test.Name=RX ILK V=0V



Statistics: (A)

Max	-36.839E-09	25%	-123.048E-09	SpecHigh	10.000E-06
Mean	-122.455E-09	10%	-166.740E-09	SpecLow	-10.000E-06
Min	-660.111E-09	N	78	PctWithinSpec	100.00
Range	623.271E-09	Cp	>4.0000	c	
StdDev	69.341E-09	Cpl	>4.0000	PctDefSpec	0
W	0.4633	Cpu	>4.0000	NWithinSpec	78
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	-74.491E-09	Skew	-6.2074		
75%	-104.333E-09	Kurtosis	47.8229		
Median	-113.062E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

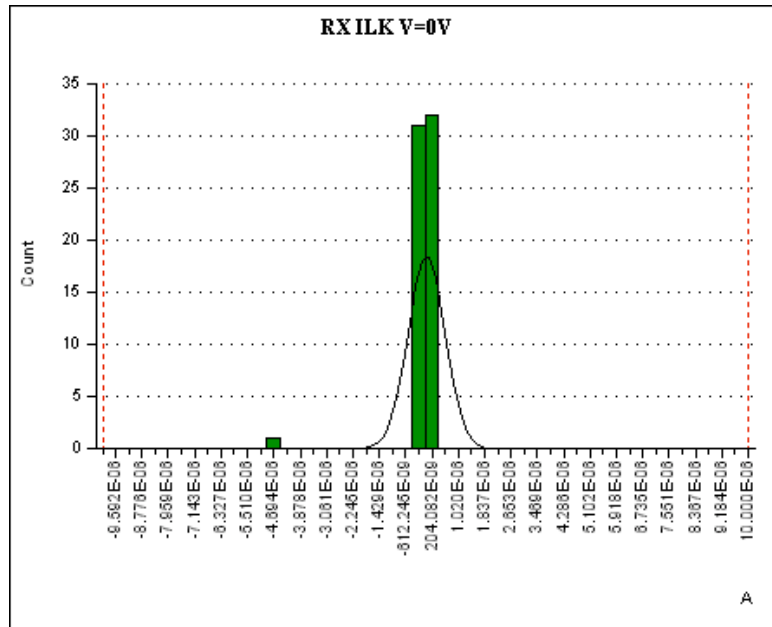
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=7.001, Test.Name=RX ILK V=0V



Statistics: (A)

Max	21.769E-09	25%	-10.059E-09	SpecHigh	10.000E-06
Mean	-76.280E-09	10%	-18.790E-09	SpecLow	-10.000E-06
Min	-4.522E-06	N	64	PctWithinSpec	100.00
Range	4.544E-06	Cp	>4.0000	PctDefSpec	0
StdDev	565.751E-09	Cpl	>4.0000	NWithinSpec	64
W	0.1325	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	15.972E-09	Skew	-7.9487		
75%	10.626E-09	Kurtosis	63.4311		
Median	-479.459E-12				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

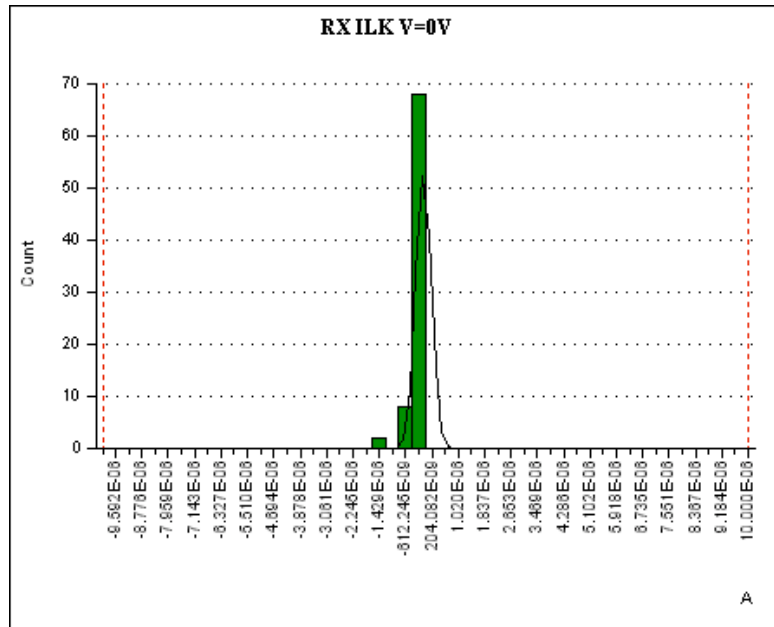
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.001, Test.Name=RX ILK V=0V



Statistics: (A)

Max	-25.937E-09	25%	-108.163E-09	SpecHigh	10.000E-06
Mean	-174.335E-09	10%	-449.085E-09	SpecLow	-10.000E-06
Min	-1.550E-06	N	78	PctWithinSpec	100.00
Range	1.524E-06	Cp	>4.0000	c	
StdDev	241.365E-09	Cpl	>4.0000	PctDefSpec	0
W	0.4543	Cpu	>4.0000	NWithinSpec	78
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	-76.702E-09	Skew	-3.9713		
75%	-83.701E-09	Kurtosis	17.9487		
Median	-90.444E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

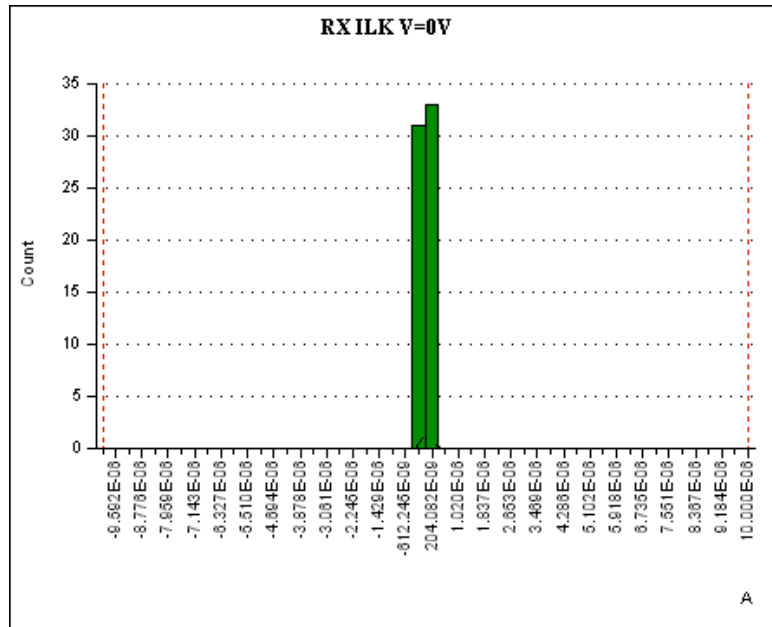
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.002, Test.Name=RX ILK V=0V



Statistics: (A)

Max	20.889E-09	25%	-15.364E-09	SpecHigh	10.000E-06
Mean	-10.194E-09	10%	-20.193E-09	SpecLow	-10.000E-06
Min	-382.356E-09	N	64	PctWithinSpec	100.00
Range	403.245E-09	Cp	>4.0000	c	
StdDev	58.993E-09	Cpl	>4.0000	PctDefSpec	0
W	0.4481	Cpu	>4.0000	NWithinSpec	64
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	19.433E-09	Skew	-4.7945		
75%	15.612E-09	Kurtosis	26.6822		
Median	8.243E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

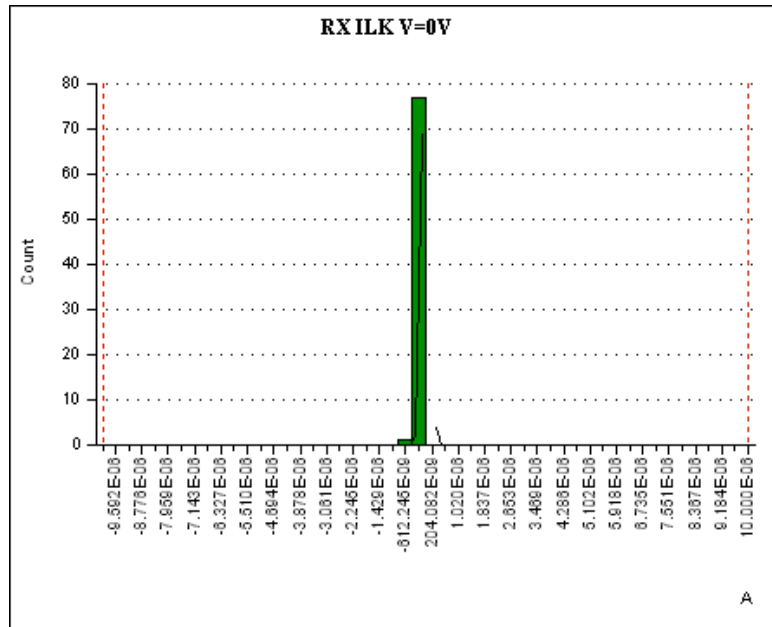
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.002, Test.Name=RX ILK V=0V



Statistics: (A)

Max	-24.094E-09	25%	-63.733E-09	SpecHigh	10.000E-06
Mean	-88.396E-09	10%	-224.876E-09	SpecLow	-10.000E-06
Min	-664.088E-09	N	78	PctWithinSpec	100.00
Range	639.994E-09	Cp	>4.0000	PctDefSpec	0
StdDev	111.089E-09	Cpl	>4.0000	NWithinSpec	78
W	0.5542	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	-31.017E-09	Skew	-2.9797		
75%	-37.724E-09	Kurtosis	10.1000		
Median	-44.539E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

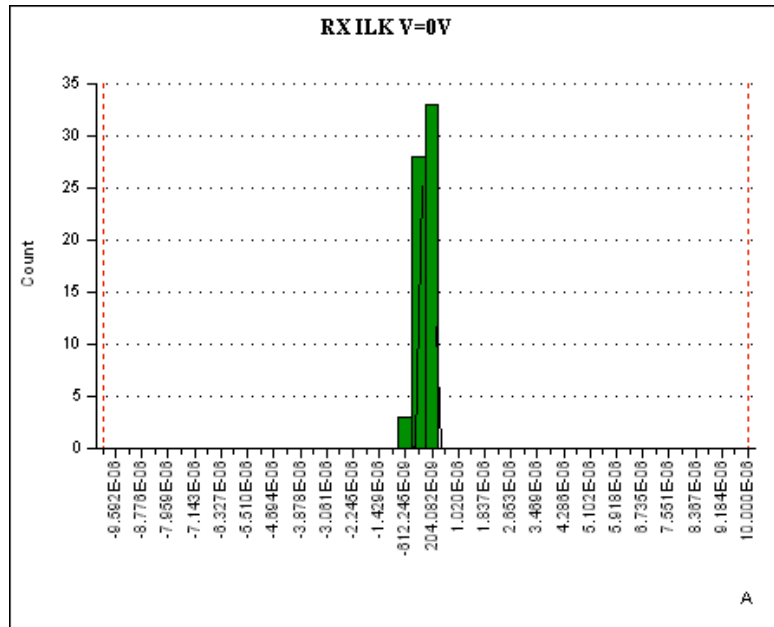
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.003, Test.Name=RX ILK V=0V



Statistics: (A)

Max	23.999E-09	25%	-11.902E-09	SpecHigh	10.000E-06
Mean	-22.566E-09	10%	-21.962E-09	SpecLow	-10.000E-06
Min	-533.285E-09	N	64	PctWithinSpec	100.00
Range	557.284E-09	Cp	>4.0000	PctDefSpec	0
StdDev	108.376E-09	Cpl	>4.0000	NWithinSpec	64
W	0.3833	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	22.083E-09	Skew	-3.9133		
75%	19.431E-09	Kurtosis	14.6920		
Median	1.657E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

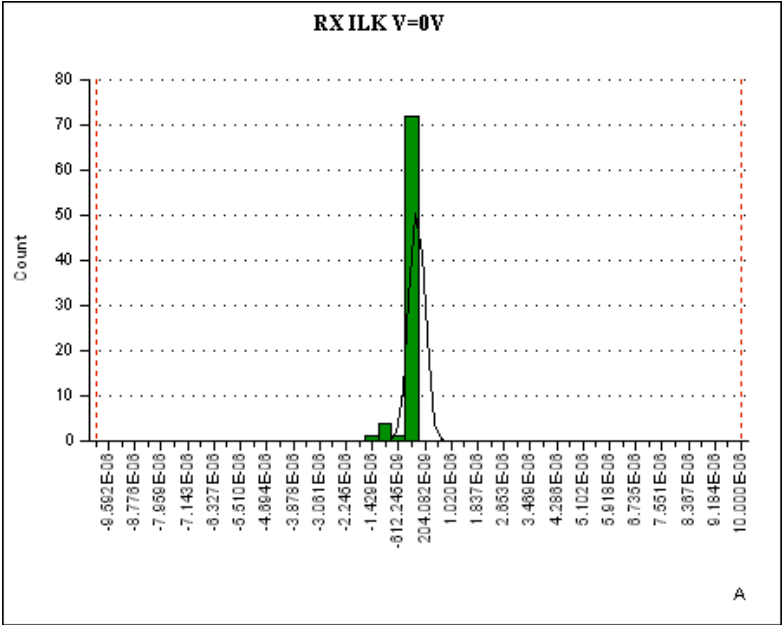
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.003, Test.Name=RX ILK V=0V



Statistics: (A)

Max	-55.994E-09	25%	-96.965E-09	SpecHigh	10.000E-06
Mean	-160.086E-09	10%	-178.825E-09	SpecLow	-10.000E-06
Min	-1.227E-06	N	78	PctWithinSpec	100.00
Range	1.171E-06	Cp	>4.0000	c	
StdDev	248.180E-09	Cpl	>4.0000	PctDefSpec	0
W	0.3727	Cpu	>4.0000	NWithinSpec	78
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	-68.524E-09	Skew	-3.4346		
75%	-78.692E-09	Kurtosis	10.7527		
Median	-89.596E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

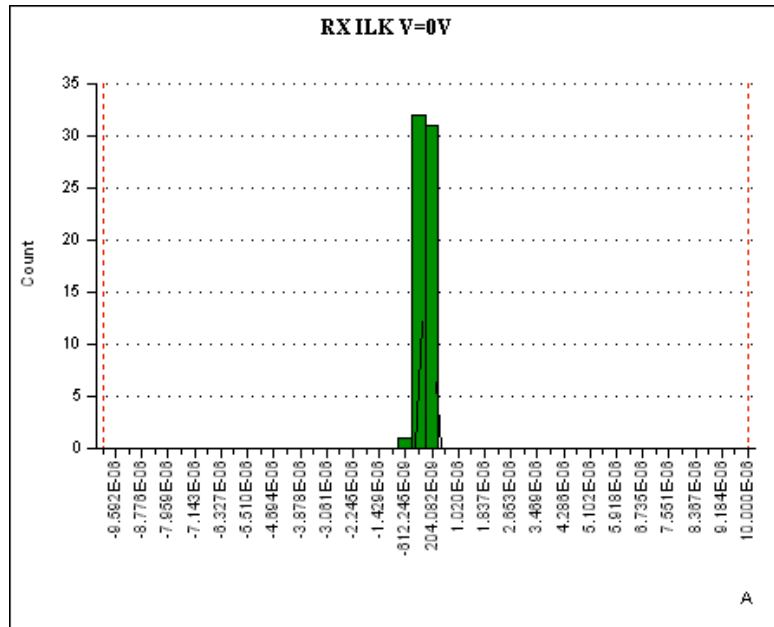
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=7.004, Test.Name=RX ILK V=0V



Statistics: (A)

Max	72.046E-09	25%	-15.108E-09	SpecHigh	10.000E-06
Mean	-12.672E-09	10%	-20.782E-09	SpecLow	-10.000E-06
Min	-674.534E-09	N	64	PctWithinSpec	100.00
Range	746.579E-09	Cp	>4.0000	PctDefSpec	0
StdDev	87.647E-09	Cpl	>4.0000	NWithinSpec	64
W	0.2954	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	17.295E-09	Skew	-7.0568		
75%	14.643E-09	Kurtosis	53.6803		
Median	-5.858E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

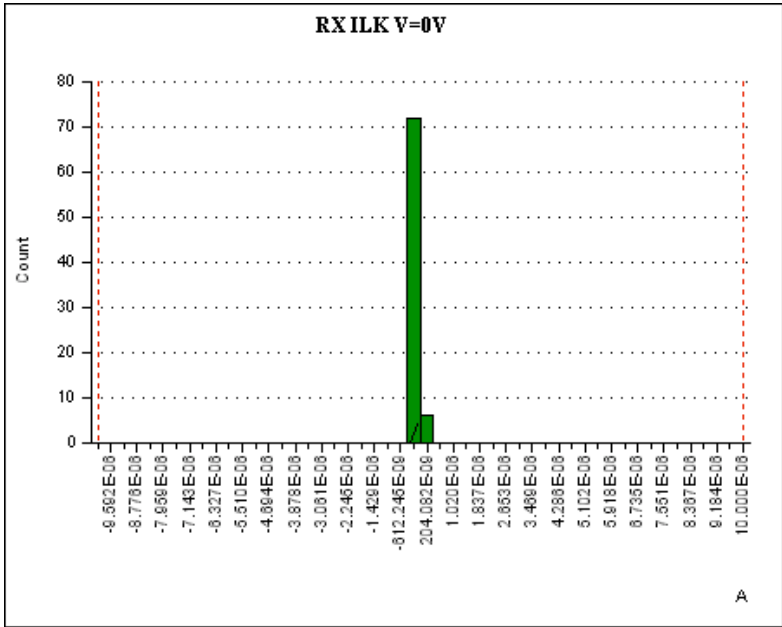
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.004, Test.Name=RX ILK V=0V



Statistics: (A)

Max	307.920E-09	25%	-72.061E-09	SpecHigh	10.000E-06
Mean	-54.246E-09	10%	-95.122E-09	SpecLow	-10.000E-06
Min	-132.995E-09	N	78	PctWithinSpec	100.00
Range	440.915E-09	Cp	>4.0000	c	
StdDev	50.935E-09	Cpl	>4.0000	PctDefSpec	0
W	0.5730	Cpu	>4.0000	NWithinSpec	78
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	-15.031E-09	Skew	4.9250		
75%	-51.796E-09	Kurtosis	33.3991		
Median	-63.991E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

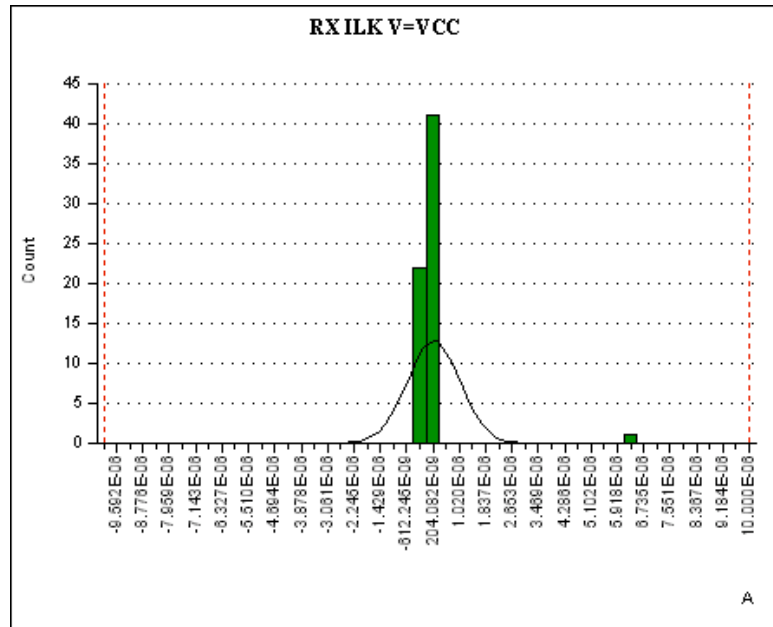
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=7.005, Test.Name=RX ILK V=VCC



Statistics: (A)

Max	6.515E-06	25%	-7.406E-09	SpecHigh	10.000E-06
Mean	109.342E-09	10%	-14.002E-09	SpecLow	-10.000E-06
Min	-21.888E-09	N	64	PctWithinSpec	100.00
Range	6.537E-06	Cp	>4.0000	c	
StdDev	813.584E-09	Cpl	>4.0000	PctDefSpec	0
W	0.1165	Cpu	>4.0000	NWithinSpec	64
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	23.206E-09	Skew	7.9955		
75%	19.875E-09	Kurtosis	63.9509		
Median	13.759E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

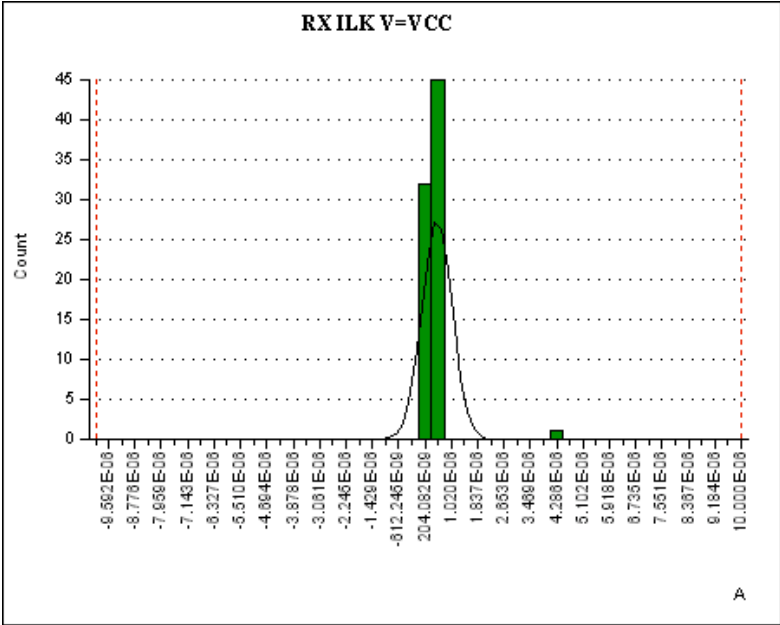
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.005, Test.Name=RX ILK V=VCC



Statistics: (A)

Max	4.390E-06	25%	403.705E-09	SpecHigh	10.000E-06
Mean	461.093E-09	10%	257.002E-09	SpecLow	-10.000E-06
Min	153.261E-09	N	78	PctWithinSpec	100.00
Range	4.236E-06	Cp	>4.0000	c	
StdDev	462.312E-09	Cpl	>4.0000	PctDefSpec	0
W	0.2389	Cpu	>4.0000	NWithinSpec	78
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	542.081E-09	Skew	8.1625		
75%	425.736E-09	Kurtosis	70.0949		
Median	412.620E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

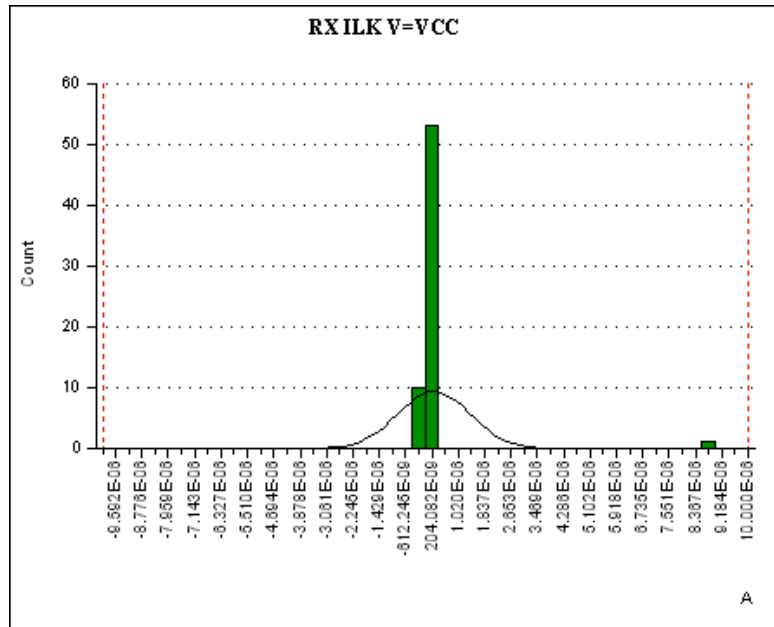
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=7.006, Test.Name=RX ILK V=VCC



Statistics: (A)

Max	8.858E-06	25%	3.610E-09	SpecHigh	10.000E-06
Mean	155.459E-09	10%	-2.136E-09	SpecLow	-10.000E-06
Min	-14.518E-09	N	64	PctWithinSpec	100.00
Range	8.872E-06	Cp	3.0161	PctDefSpec	0
StdDev	1.105E-06	Cpl	3.0630	NWithinSpec	64
W	0.1141	Cpu	2.9692	NOutsideSpec	0
WpValue	0.0000	Cpk	2.9692		
90%	30.851E-09	Skew	7.9966		
75%	25.142E-09	Kurtosis	63.9631		
Median	18.917E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

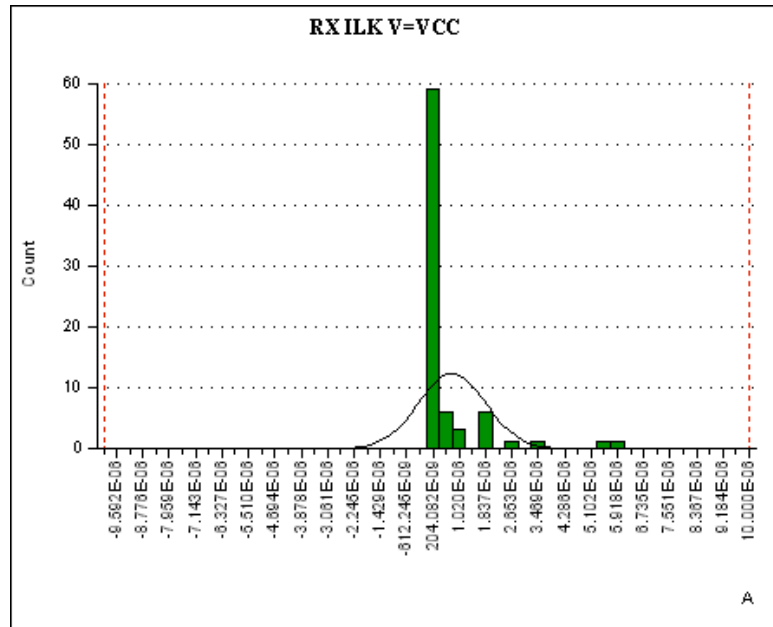
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.006, Test.Name=RX ILK V=VCC



Statistics: (A)

Max	6.055E-06	25%	292.445E-09	SpecHigh	10.000E-06
Mean	679.501E-09	10%	281.685E-09	SpecLow	-10.000E-06
Min	169.767E-09	N	78	PctWithinSpec	100.00
Range	5.885E-06	Cp	3.2449	PctDefSpec	0
StdDev	1.027E-06	Cpl	3.4654	NWithinSpec	78
W	0.4532	Cpu	3.0244	NOutsideSpec	0
WpValue	0.0000	Cpk	3.0244		
90%	1.900E-06	Skew	3.7054		
75%	396.411E-09	Kurtosis	15.1779		
Median	301.729E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

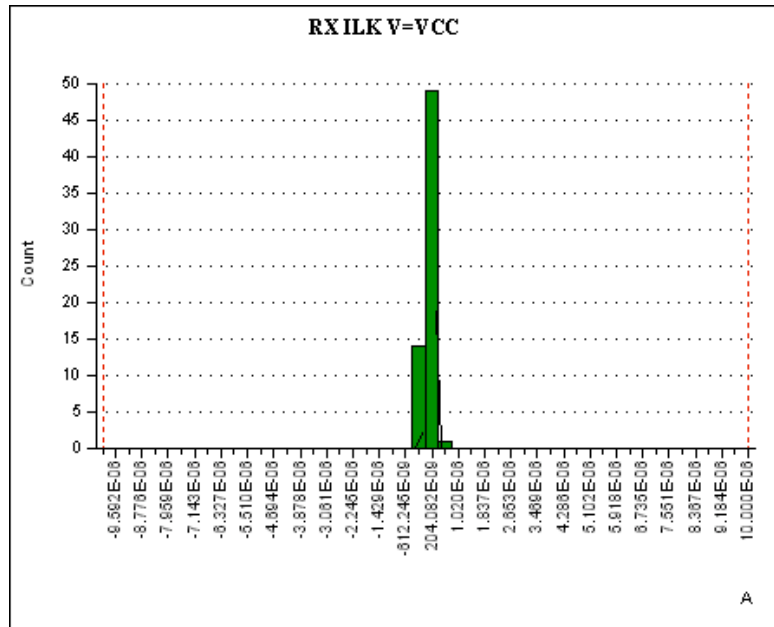
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.007, Test.Name=RX ILK V=VCC



Statistics: (A)

Max	551.584E-09	25%	4.235E-09	SpecHigh	10.000E-06
Mean	37.637E-09	10%	-7.738E-09	SpecLow	-10.000E-06
Min	-21.591E-09	N	64	PctWithinSpec	100.00
Range	573.174E-09	Cp	>4.0000	PctDefSpec	0
StdDev	83.320E-09	Cpl	>4.0000	NWithinSpec	64
W	0.4878	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	99.836E-09	Skew	4.5895		
75%	26.089E-09	Kurtosis	24.8357		
Median	21.124E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

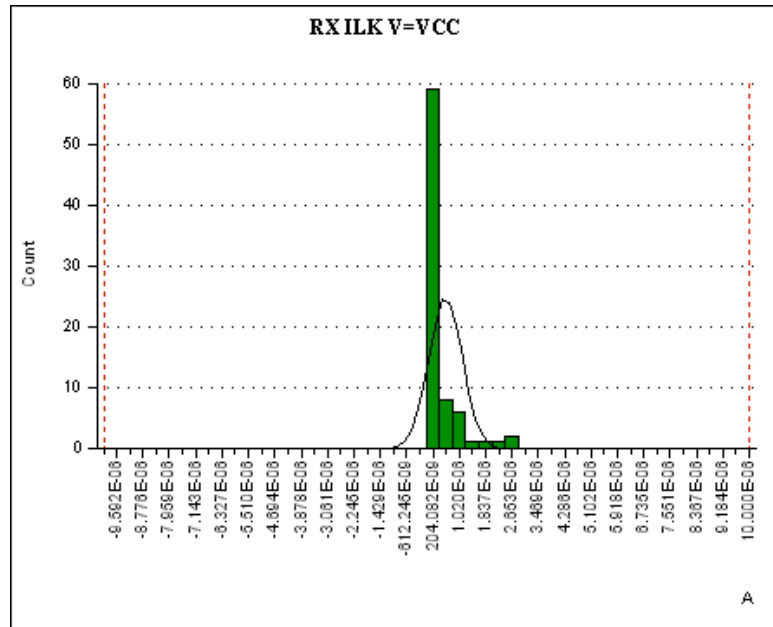
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.007, Test.Name=RX ILK V=VCC



Statistics: (A)

Max	2.743E-06	25%	255.015E-09	SpecHigh	10.000E-06
Mean	477.766E-09	10%	244.333E-09	SpecLow	-10.000E-06
Min	129.831E-09	N	78	PctWithinSpec	100.00
Range	2.613E-06	Cp	>4.0000	PctDefSpec	0
StdDev	513.542E-09	Cpl	>4.0000	NWithinSpec	78
W	0.5459	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	1.009E-06	Skew	2.9451		
75%	403.557E-09	Kurtosis	9.0666		
Median	262.347E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

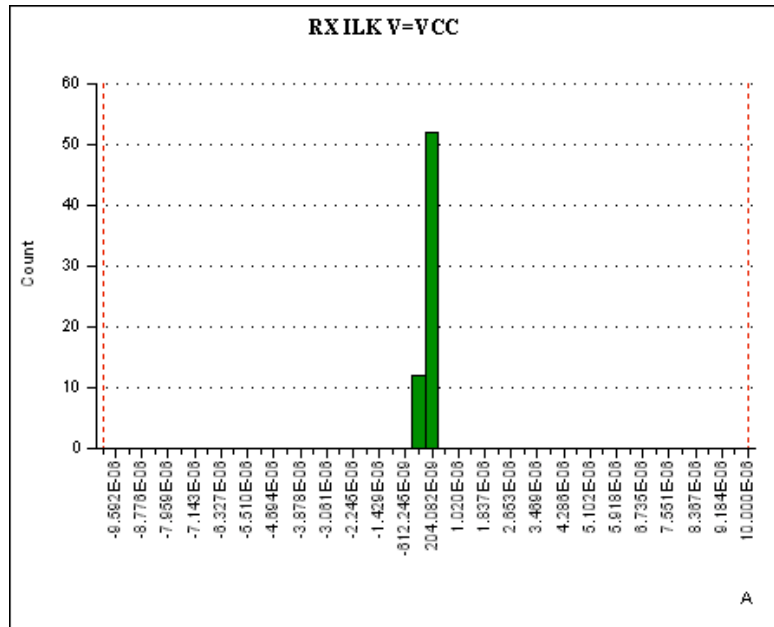
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.008, Test.Name=RX ILK V=VCC



Statistics: (A)

Max	213.645E-09	25%	2.320E-09	SpecHigh	10.000E-06
Mean	27.039E-09	10%	-4.274E-09	SpecLow	-10.000E-06
Min	-13.118E-09	N	64	PctWithinSpec	100.00
Range	226.763E-09	Cp	>4.0000	PctDefSpec	0
StdDev	39.568E-09	Cpl	>4.0000	NWithinSpec	64
W	0.6546	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	62.098E-09	Skew	2.9460		
75%	29.684E-09	Kurtosis	10.1022		
Median	22.859E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

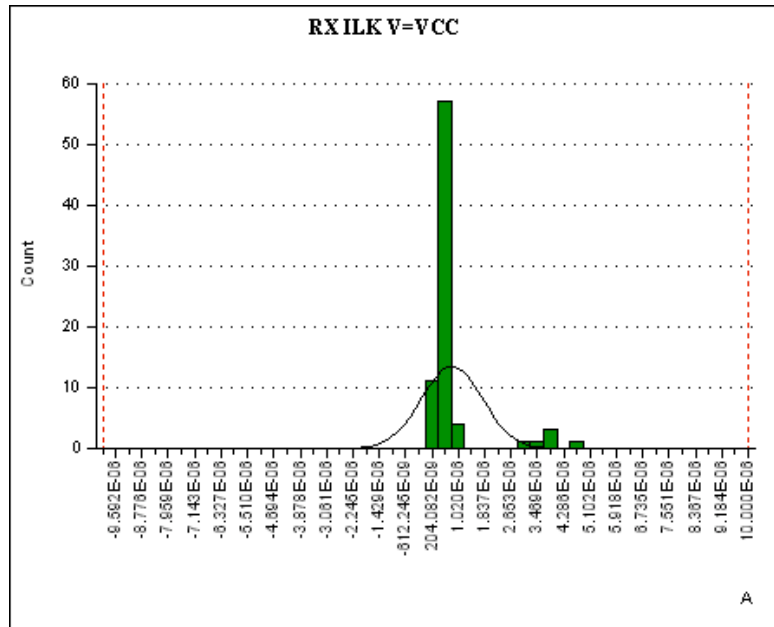
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.008, Test.Name=RX ILK V=VCC



Statistics: (A)

Max	4.831E-06	25%	415.052E-09	SpecHigh	10.000E-06
Mean	713.342E-09	10%	331.937E-09	SpecLow	-10.000E-06
Min	230.846E-09	N	78	PctWithinSpec	100.00
Range	4.600E-06	Cp	3.5738	PctDefSpec	0
StdDev	932.722E-09	Cpl	3.8287	NWithinSpec	78
W	0.4073	Cpu	3.3188	NOutsideSpec	0
WpValue	0.0000	Cpk	3.3188		
90%	1.045E-06	Skew	3.2758		
75%	439.366E-09	Kurtosis	9.7198		
Median	423.194E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

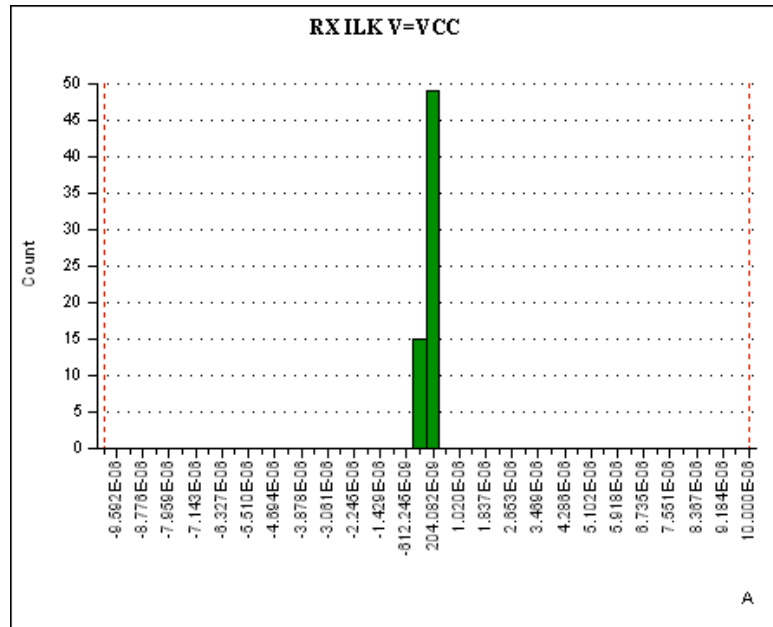
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.009, Test.Name=RX ILK V=VCC



Statistics: (A)

Max	267.880E-09	25%	660.467E-12	SpecHigh	10.000E-06
Mean	25.637E-09	10%	-6.337E-09	SpecLow	-10.000E-06
Min	-16.360E-09	N	64	PctWithinSpec	100.00
Range	284.240E-09	Cp	>4.0000	c	
StdDev	44.102E-09	Cpl	>4.0000	PctDefSpec	0
W	0.6068	Cpu	>4.0000	NWithinSpec	64
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	39.270E-09	Skew	3.6382		
75%	31.002E-09	Kurtosis	16.4841		
Median	25.031E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

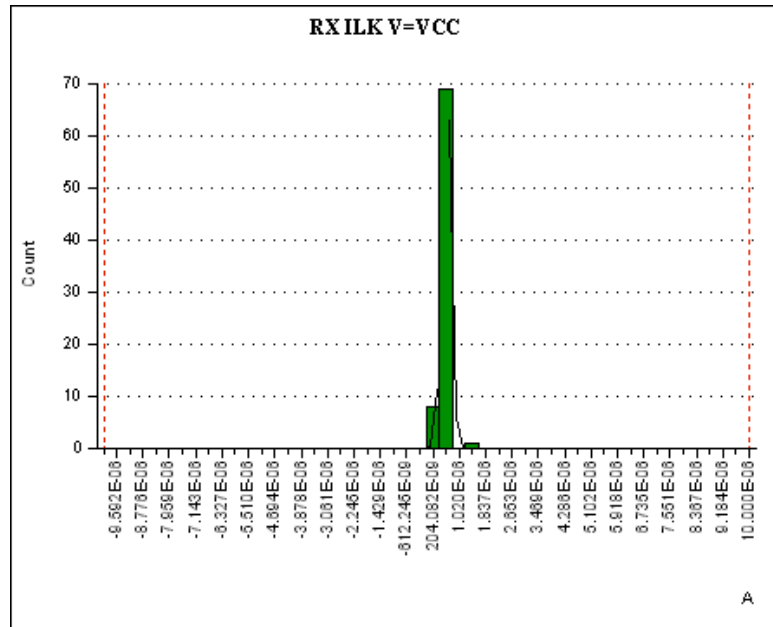
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.009, Test.Name=RX ILK V=VCC



Statistics: (A)

Max	1.257E-06	25%	428.019E-09	SpecHigh	10.000E-06
Mean	479.580E-09	10%	402.086E-09	SpecLow	-10.000E-06
Min	273.804E-09	N	78	PctWithinSpec	100.00
Range	982.919E-09	Cp	>4.0000	PctDefSpec	0
StdDev	136.327E-09	Cpl	>4.0000	NWithinSpec	78
W	0.6593	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	674.709E-09	Skew	3.0457		
75%	460.737E-09	Kurtosis	13.3941		
Median	438.777E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

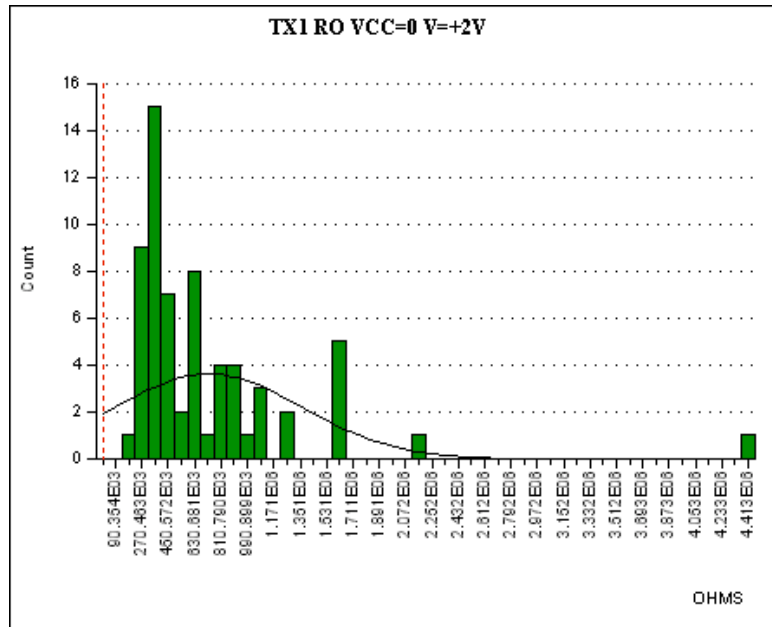
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=8.000, Test.Name=TX1 RO VCC=0 V=+2V



Statistics: (OHMS)

Max	4.413E06	25%	361.065E03	SpecHigh	N/A
Mean	723.439E03	10%	301.010E03	SpecLow	300.000
Min	198.630E03	N	64	PctWithinSpec	100.00
Range	4.214E06	Cp	N/A	c	
StdDev	633.500E03	Cpl	0.3805	PctDefSpec	0
W	0.6554	Cpu	N/A	NWithinSpec	64
WpValue	0.0000	Cpk	0.3805	NOutsideSpec	0
90%	1.609E06	Skew	3.5530		
75%	927.115E03	Kurtosis	17.7992		
Median	513.811E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

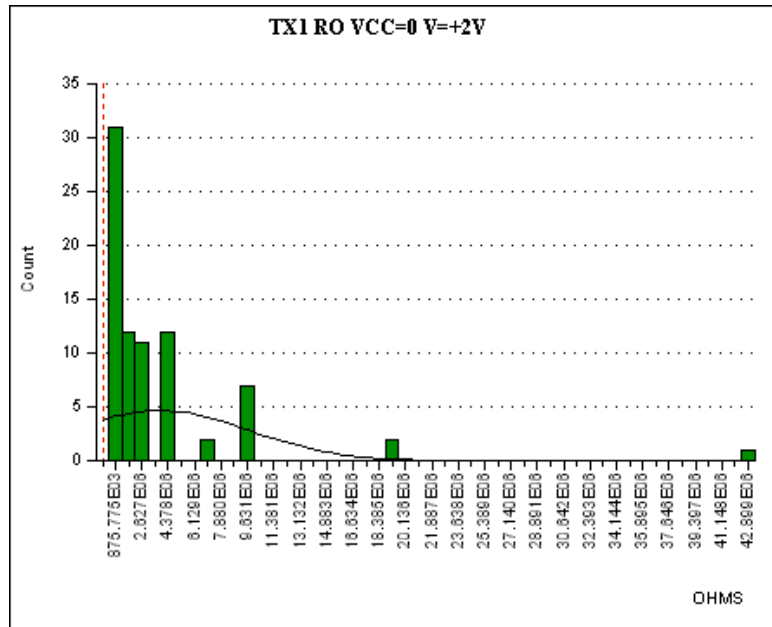
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=8.000, Test.Name=TX1 RO VCC=0 V=+2V



Statistics: (OHMS)

Max	42.899E06	25%	863.804E03	SpecHigh	N/A
Mean	3.764E06	10%	616.508E03	SpecLow	300.000
Min	529.453E03	N	78	PctWithinSpec	100.00
Range	42.369E06	Cp	N/A	PctDefSpec	0
StdDev	5.849E06	Cpl	0.2145	NWithinSpec	78
W	0.5213	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	0.2145		
90%	10.047E06	Skew	4.5178		
75%	4.676E06	Kurtosis	26.4513		
Median	1.961E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

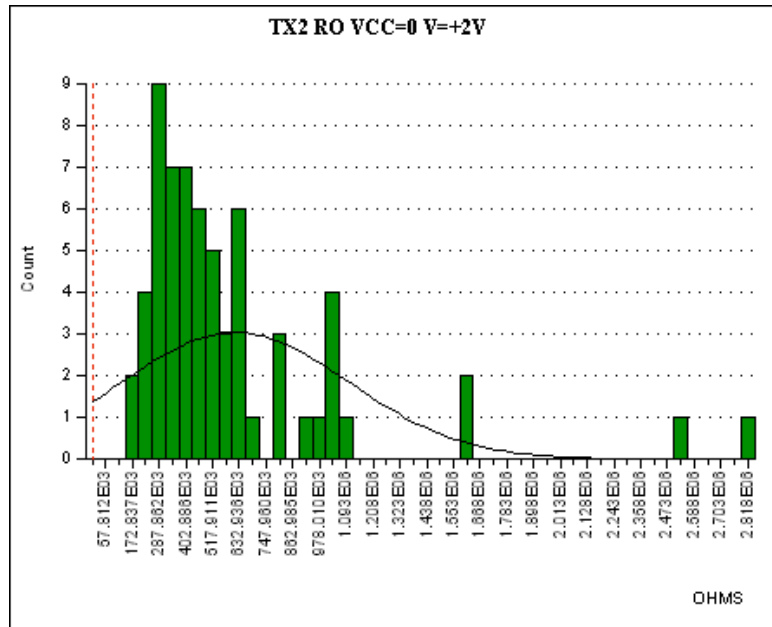
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=8.003, Test.Name=TX2 RO VCC=0 V=+2V



Statistics: (OHMS)

Max	2.818E06	25%	340.230E03	SpecHigh	N/A
Mean	608.893E03	10%	262.101E03	SpecLow	300.000
Min	163.900E03	N	64	PctWithinSpec	100.00
Range	2.655E06	Cp	N/A	PctDefSpec	0
StdDev	483.649E03	Cpl	0.4194	NWithinSpec	64
W	0.6889	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	0.4194		
90%	1.037E06	Skew	2.8521		
75%	636.259E03	Kurtosis	9.7452		
Median	462.517E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

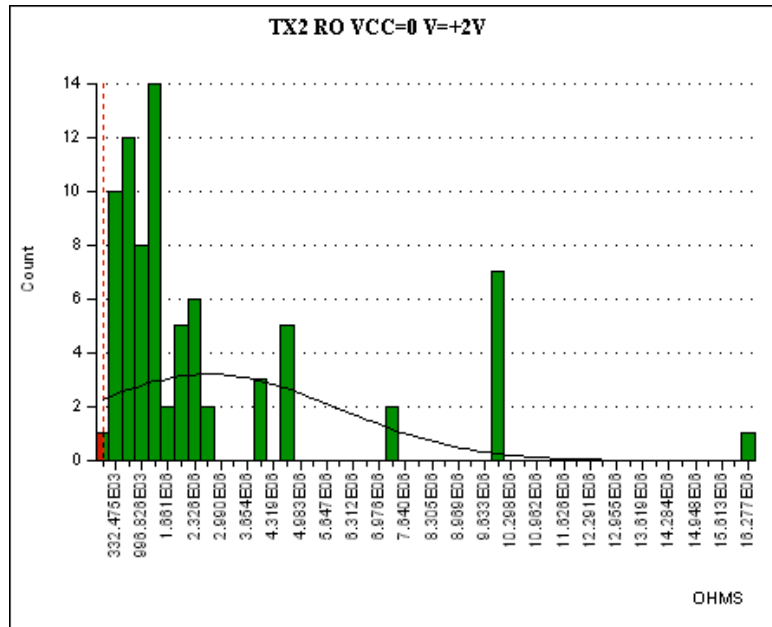
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=8.003, Test.Name=TX2 RO VCC=0 V=+2V



Statistics: (OHMS)

Max	16.277E06	25%	781.736E03	SpecHigh	N/A
Mean	2.668E06	10%	455.884E03	SpecLow	300.000
Min	116.382E03	N	78	PctWithinSpec	100.00
Range	16.161E06	Cp	N/A	PctDefSpec	0
StdDev	3.215E06	Cpl	0.2765	NWithinSpec	78
W	0.6977	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	0.2765		
90%	10.044E06	Skew	2.1099		
75%	2.527E06	Kurtosis	4.3266		
Median	1.410E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

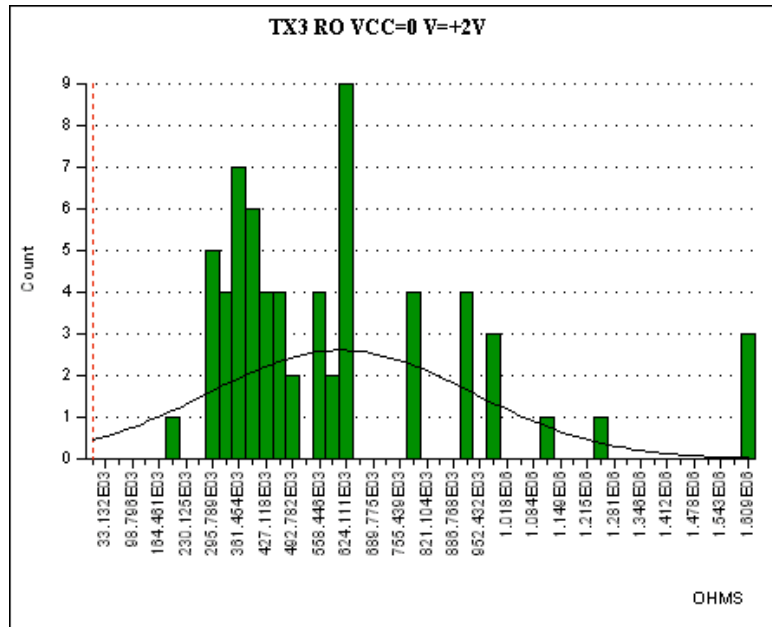
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=8.004, Test.Name=TX3 RO VCC=0 V=+2V



Statistics: (OHMS)

Max	1.609E06	25%	363.550E03	SpecHigh	N/A
Mean	604.793E03	10%	331.414E03	SpecLow	300.000
Min	188.637E03	N	64	PctWithinSpec	100.00
Range	1.420E06	Cp	N/A	PctDefSpec	0
StdDev	321.543E03	Cpl	0.6267	NWithinSpec	64
W	0.8267	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	0.6267		
90%	997.611E03	Skew	1.6241		
75%	711.691E03	Kurtosis	2.6194		
Median	493.566E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

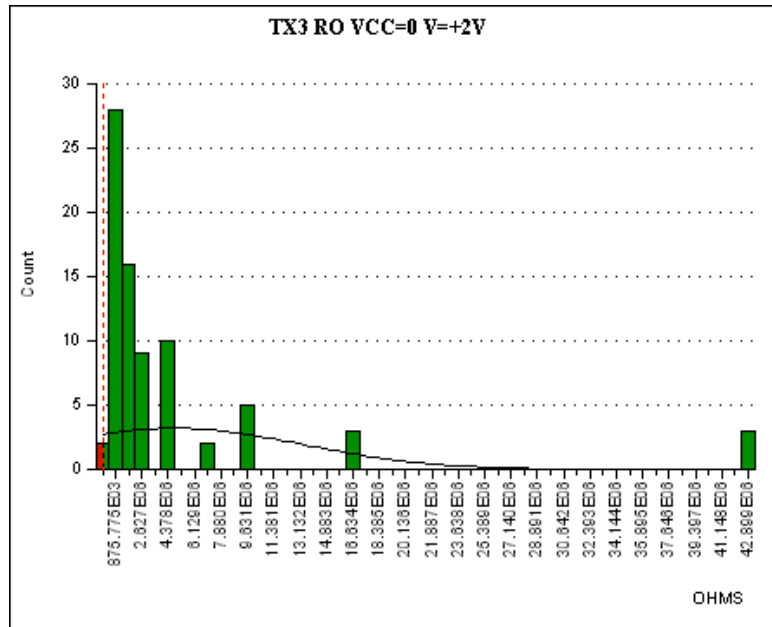
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=8.004, Test.Name=TX3 RO VCC=0 V=+2V



Statistics: (OHMS)

Max	42.899E06	25%	863.804E03	SpecHigh	N/A
Mean	4.604E06	10%	616.508E03	SpecLow	300.000
Min	334.050E03	N	78	PctWithinSpec	100.00
Range	42.565E06	Cp	N/A	PctDefSpec	0
StdDev	8.514E06	Cpl	0.1802	NWithinSpec	78
W	0.4752	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	0.1802		
90%	10.047E06	Skew	3.7074		
75%	4.109E06	Kurtosis	14.2635		
Median	1.452E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

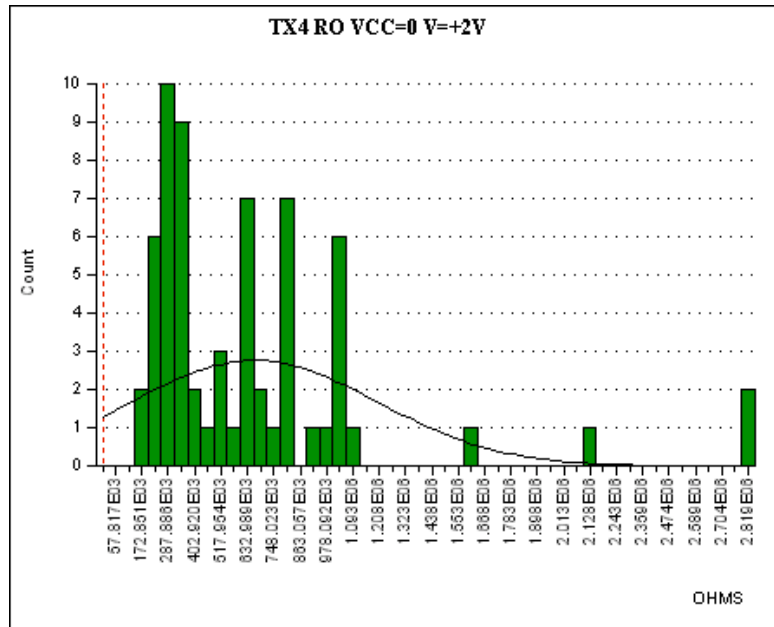
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=8.007, Test.Name=TX4 RO VCC=0 V=+2V



Statistics: (OHMS)

Max	2.819E06	25%	301.010E03	SpecHigh	N/A
Mean	655.728E03	10%	244.978E03	SpecLow	300.000
Min	173.659E03	N	64	PctWithinSpec	100.00
Range	2.645E06	Cp	N/A	PctDefSpec	0
StdDev	531.597E03	Cpl	0.4110	NWithinSpec	64
W	0.7188	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	0.4110		
90%	1.037E06	Skew	2.5421		
75%	787.967E03	Kurtosis	7.8035		
Median	543.525E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

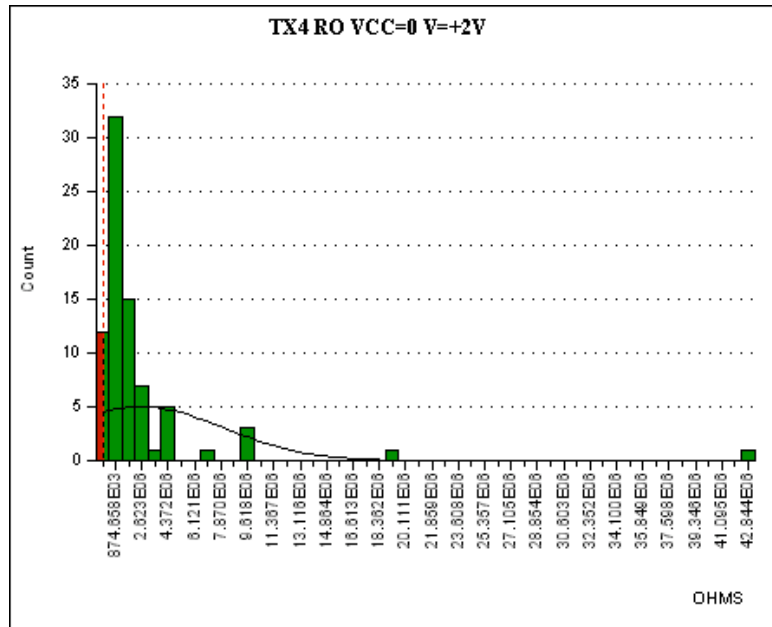
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=8.007, Test.Name=TX4 RO VCC=0 V=+2V



Statistics: (OHMS)

Max	42.844E06	25%	616.497E03	SpecHigh	N/A
Mean	2.533E06	10%	293.035E03	SpecLow	300.000
Min	120.663E03	N	78	PctWithinSpec	100.00
Range	42.723E06	Cp	N/A	PctDefSpec	0
StdDev	5.434E06	Cpl	0.1554	NWithinSpec	78
W	0.3792	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	0.1554		
90%	4.676E06	Skew	5.9006		
75%	2.119E06	Kurtosis	40.7520		
Median	1.120E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

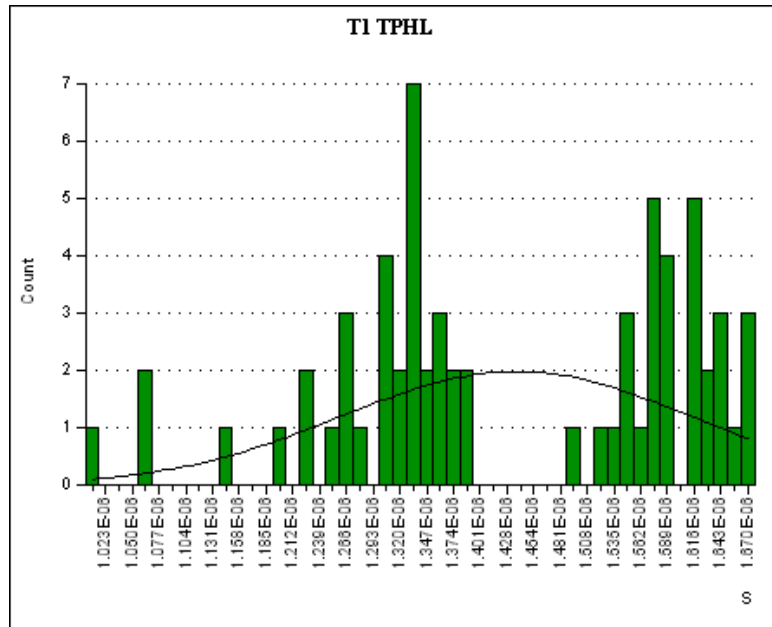
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=9.000, Test.Name=T1 TPHL



Statistics: (S)

Max	1.670E-06	25%	1.315E-06	SpecHigh	N/A
Mean	1.432E-06	10%	1.230E-06	SpecLow	N/A
Min	1.010E-06	N	64	PctWithinSpec	N/A
Range	659.999E-09	Cp	N/A	PctDefSpec	N/A
StdDev	173.324E-09	Cpl	N/A	NWithinSpec	N/A
W	0.9160	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0003	Cpk	N/A		
90%	1.640E-06	Skew	-0.3653		
75%	1.590E-06	Kurtosis	-0.7847		
Median	1.385E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

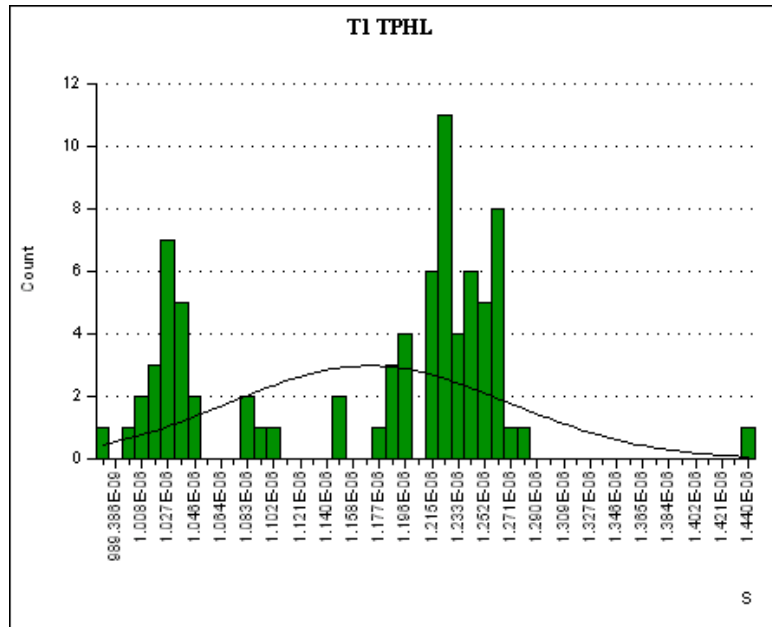
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.000, Test.Name=T1 TPHL



Statistics: (S)

Max	1.440E-06	25%	1.050E-06	SpecHigh	N/A
Mean	1.168E-06	10%	1.030E-06	SpecLow	N/A
Min	979.999E-09	N	78	PctWithinSpec	N/A
Range	460.000E-09	Cp	N/A	PctDefSpec	N/A
StdDev	98.025E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8543	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.260E-06	Skew	-0.3842		
75%	1.240E-06	Kurtosis	-0.6758		
Median	1.210E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

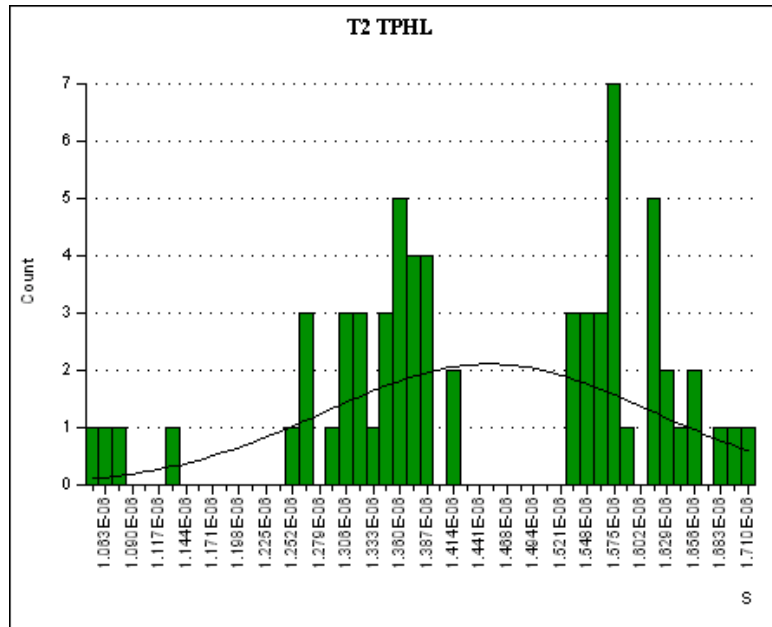
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.001, Test.Name=T2 TPHL



Statistics: (S)

Max	1.710E-06	25%	1.335E-06	SpecHigh	N/A
Mean	1.445E-06	10%	1.270E-06	SpecLow	N/A
Min	1.050E-06	N	64	PctWithinSpec	N/A
Range	659.999E-09	Cp	N/A	PctDefSpec	N/A
StdDev	163.017E-09	Cpl	N/A	NWithinSpec	N/A
W	0.9349	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0022	Cpk	N/A		
90%	1.630E-06	Skew	-0.4308		
75%	1.575E-06	Kurtosis	-0.4430		
Median	1.405E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

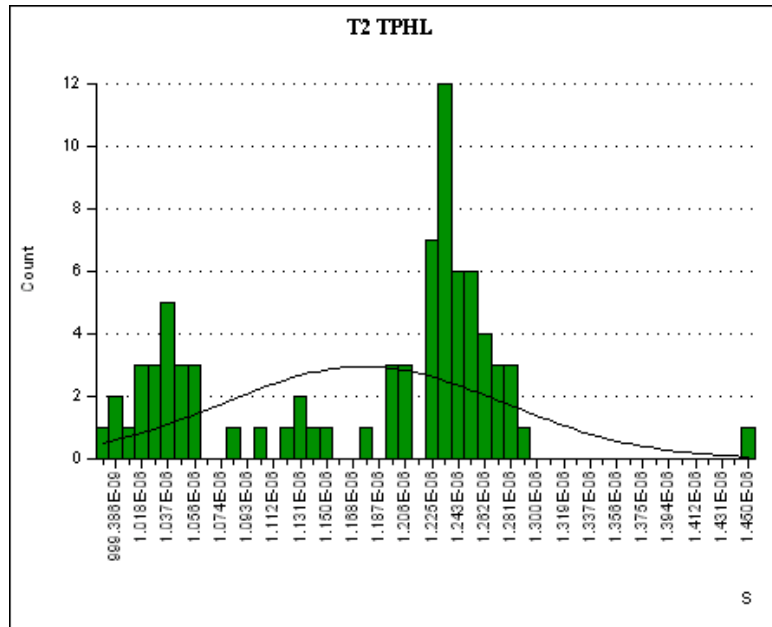
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.001, Test.Name=T2 TPHL



Statistics: (S)

Max	1.450E-06	25%	1.060E-06	SpecHigh	N/A
Mean	1.174E-06	10%	1.030E-06	SpecLow	N/A
Min	989.999E-09	N	78	PctWithinSpec	N/A
Range	460.000E-09	Cp	N/A	PctDefSpec	N/A
StdDev	98.833E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8665	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.270E-06	Skew	-0.3770		
75%	1.240E-06	Kurtosis	-0.6202		
Median	1.220E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

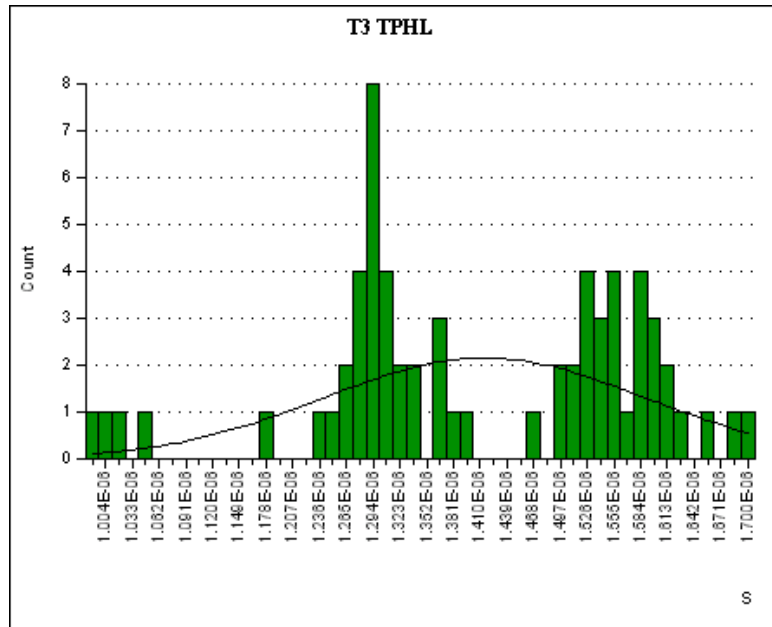
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.002, Test.Name=T3 TPHL



Statistics: (S)

Max	1.700E-06	25%	1.300E-06	SpecHigh	N/A
Mean	1.411E-06	10%	1.250E-06	SpecLow	N/A
Min	989.999E-09	N	64	PctWithinSpec	N/A
Range	710.000E-09	Cp	N/A	PctDefSpec	N/A
StdDev	171.722E-09	Cpl	N/A	NWithinSpec	N/A
W	0.9304	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0014	Cpk	N/A		
90%	1.600E-06	Skew	-0.4395		
75%	1.555E-06	Kurtosis	-0.3233		
Median	1.375E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

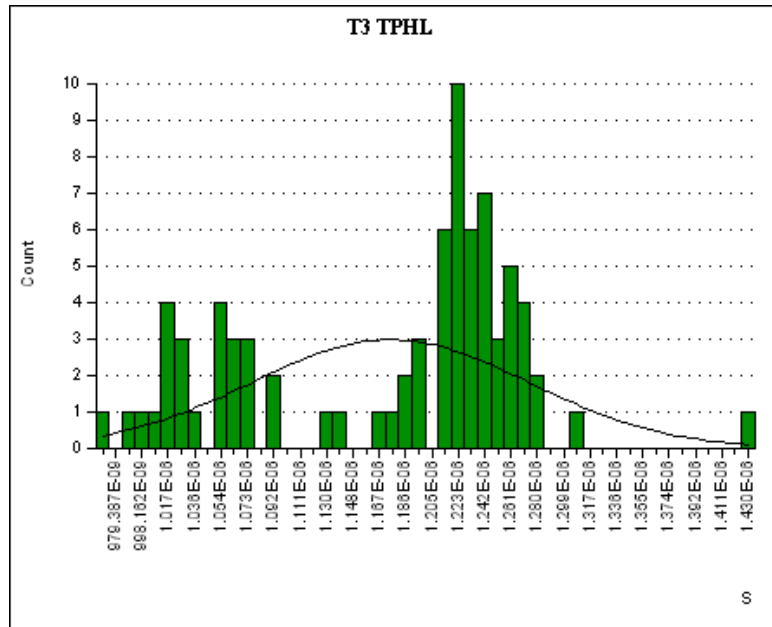
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.002, Test.Name=T3 TPHL



Statistics: (S)

Max	1.430E-06	25%	1.070E-06	SpecHigh	N/A
Mean	1.173E-06	10%	1.020E-06	SpecLow	N/A
Min	969.999E-09	N	78	PctWithinSpec	N/A
Range	460.000E-09	Cp	N/A	PctDefSpec	N/A
StdDev	97.785E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8830	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.270E-06	Skew	-0.4419		
75%	1.240E-06	Kurtosis	-0.6603		
Median	1.215E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

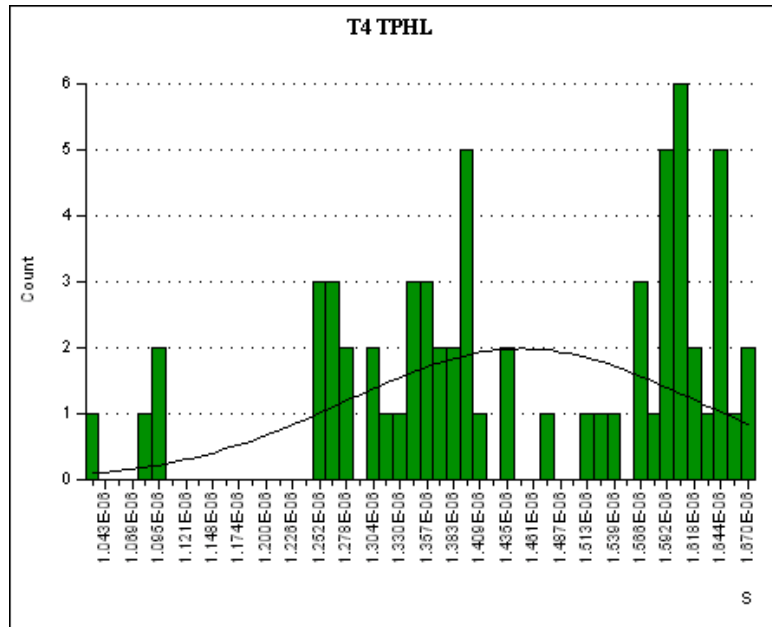
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.003, Test.Name=T4 TPHL



Statistics: (S)

Max	1.670E-06	25%	1.335E-06	SpecHigh	N/A
Mean	1.445E-06	10%	1.250E-06	SpecLow	N/A
Min	1.030E-06	N	64	PctWithinSpec	N/A
Range	639.999E-09	Cp	N/A	PctDefSpec	N/A
StdDev	167.768E-09	Cpl	N/A	NWithinSpec	N/A
W	0.9198	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0005	Cpk	N/A		
90%	1.640E-06	Skew	-0.4708		
75%	1.600E-06	Kurtosis	-0.5949		
Median	1.420E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

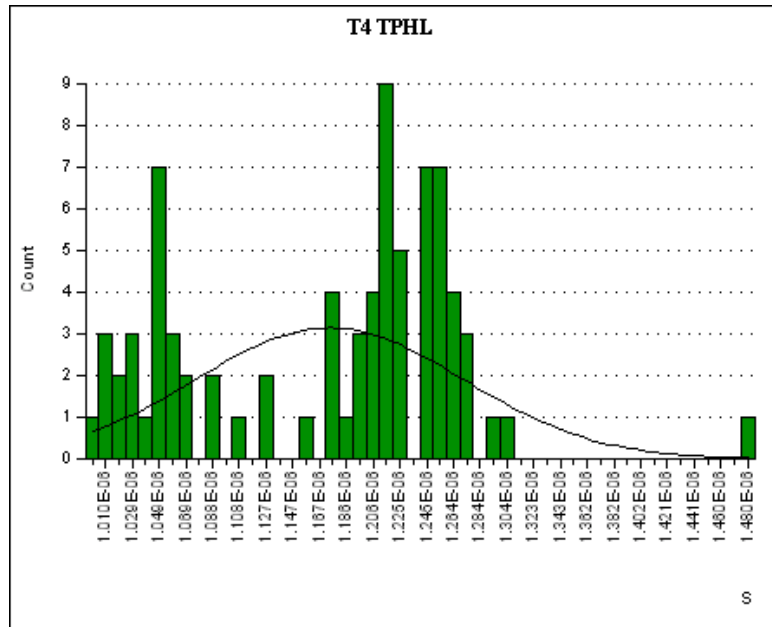
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N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.003, Test.Name=T4 TPHL



Statistics: (S)

Max	1.480E-06	25%	1.060E-06	SpecHigh	N/A
Mean	1.172E-06	10%	1.030E-06	SpecLow	N/A
Min	999.999E-09	N	78	PctWithinSpec	N/A
Range	479.999E-09	Cp	N/A	PctDefSpec	N/A
StdDev	96.847E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8836	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.260E-06	Skew	-0.1443		
75%	1.240E-06	Kurtosis	-0.1870		
Median	1.210E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

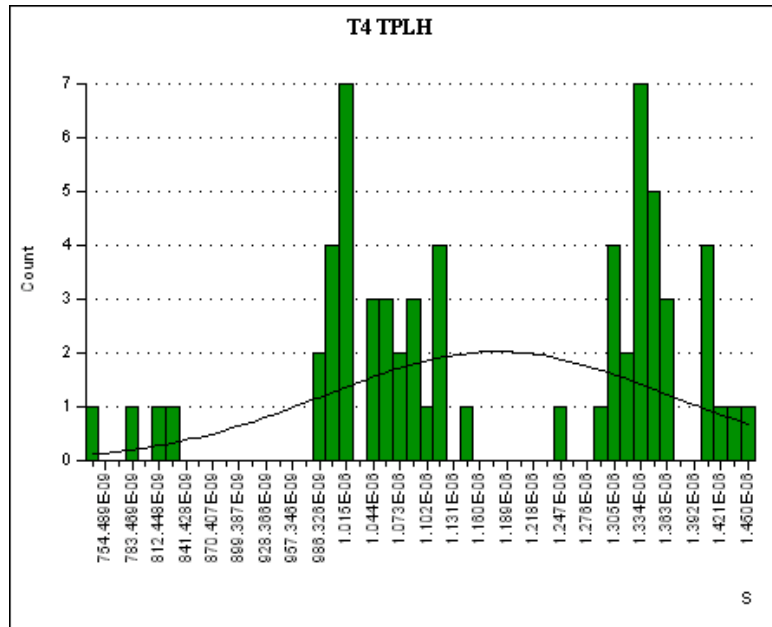
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.004, Test.Name=T4 TPLH



Statistics: (S)

Max	1.450E-06	25%	1.020E-06	SpecHigh	N/A
Mean	1.174E-06	10%	999.999E-09	SpecLow	N/A
Min	739.999E-09	N	64	PctWithinSpec	N/A
Range	709.999E-09	Cp	N/A	PctDefSpec	N/A
StdDev	182.816E-09	Cpl	N/A	NWithinSpec	N/A
W	0.9068	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0001	Cpk	N/A		
90%	1.400E-06	Skew	-0.3205		
75%	1.340E-06	Kurtosis	-0.8663		
Median	1.115E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

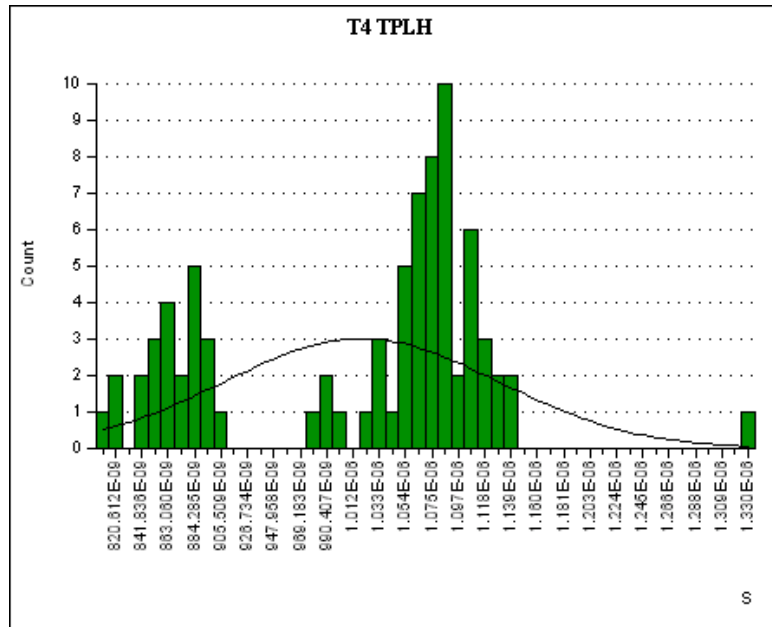
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.004, Test.Name=T4 TPLH



Statistics: (S)

Max	1.330E-06	25%	889.999E-09	SpecHigh	N/A
Mean	1.017E-06	10%	849.999E-09	SpecLow	N/A
Min	809.999E-09	N	78	PctWithinSpec	N/A
Range	519.999E-09	Cp	N/A	PctDefSpec	N/A
StdDev	109.601E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8674	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.120E-06	Skew	-0.3711		
75%	1.090E-06	Kurtosis	-0.5094		
Median	1.060E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

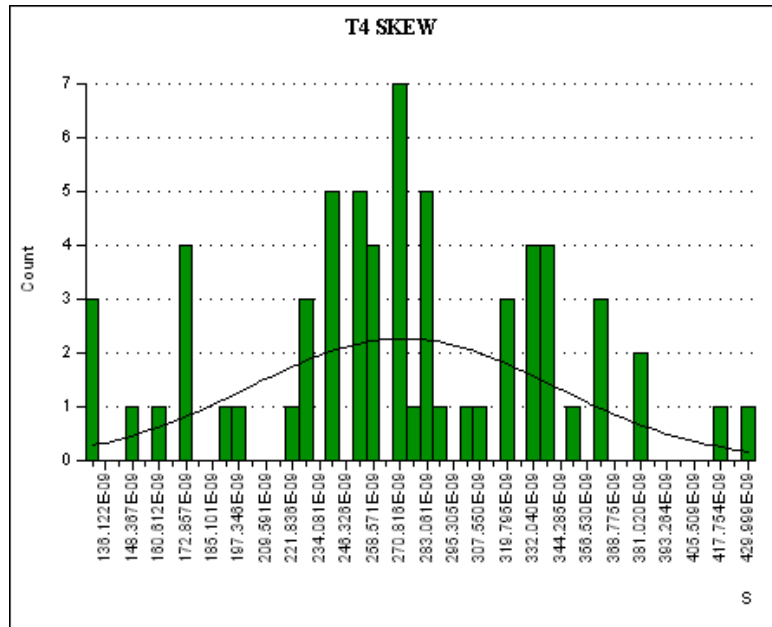
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.005, Test.Name=T4 SKEW



Statistics: (S)

Max	429.999E-09	25%	239.999E-09	SpecHigh	N/A
Mean	270.625E-09	10%	170.000E-09	SpecLow	N/A
Min	130.000E-09	N	64	PctWithinSpec	N/A
Range	300.000E-09	Cp	N/A	c	
StdDev	68.865E-09	Cpl	N/A	PctDefSpec	N/A
W	0.9757	Cpu	N/A	NWithinSpec	N/A
WpValue	0.2371	Cpk	N/A	NOutsideSpec	N/A
90%	359.999E-09	Skew	-0.0830		
75%	324.999E-09	Kurtosis	-0.1550		
Median	270.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

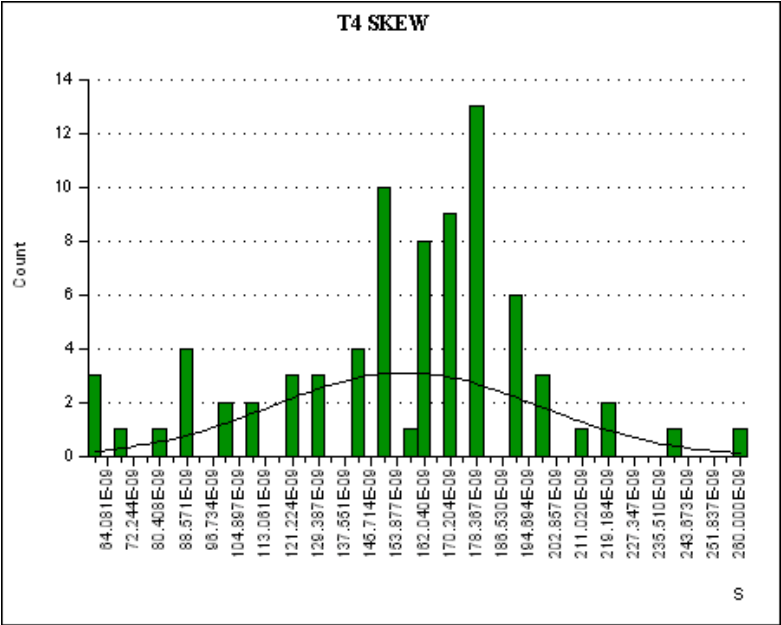
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.005, Test.Name=T4 SKEW



Statistics: (S)

Max	260.000E-09	25%	139.999E-09	SpecHigh	N/A
Mean	155.384E-09	10%	90.000E-09	SpecLow	N/A
Min	59.999E-09	N	78	PctWithinSpec	N/A
Range	200.001E-09	Cp	N/A	c	
StdDev	40.634E-09	Cpl	N/A	PctDefSpec	N/A
W	0.9544	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0071	Cpk	N/A	NOutsideSpec	N/A
90%	199.999E-09	Skew	-0.4581		
75%	180.000E-09	Kurtosis	0.3858		
Median	160.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

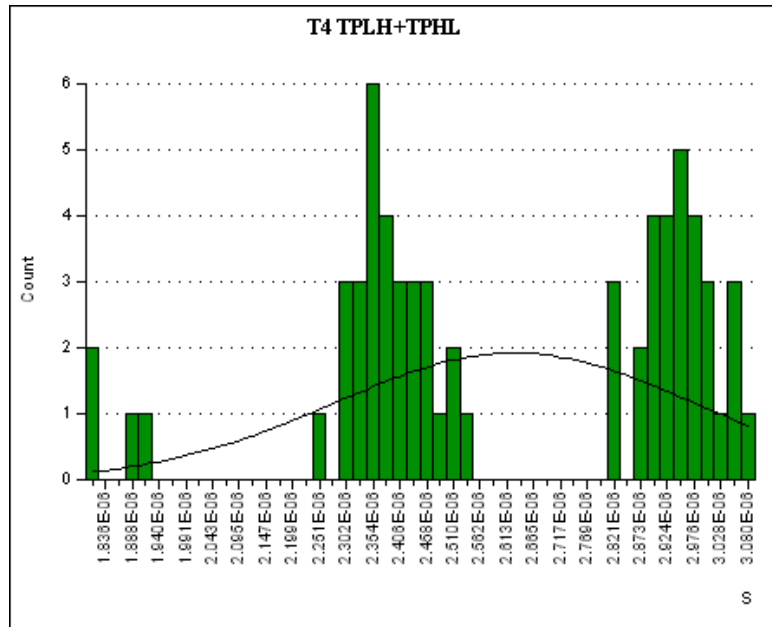
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=9.006, Test.Name=T4 TPLH+TPHL



Statistics: (S)

Max	3.080E-06	25%	2.360E-06	SpecHigh	N/A
Mean	2.619E-06	10%	2.300E-06	SpecLow	N/A
Min	1.810E-06	N	64	PctWithinSpec	N/A
Range	1.270E-06	Cp	N/A	PctDefSpec	N/A
StdDev	344.082E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8807	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	3.000E-06	Skew	-0.4042		
75%	2.940E-06	Kurtosis	-0.7383		
Median	2.505E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

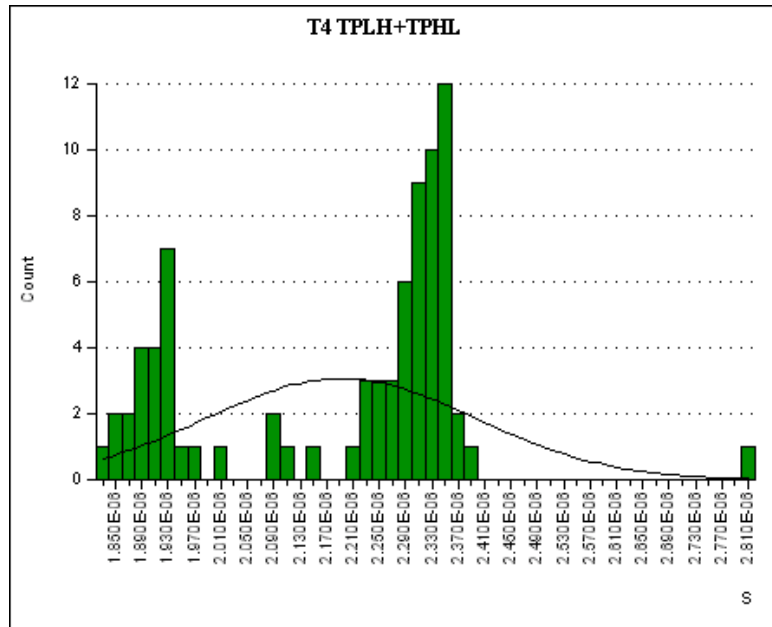
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.006, Test.Name=T4 TPLH+TPHL



Statistics: (S)

Max	2.810E-06	25%	1.940E-06	SpecHigh	N/A
Mean	2.188E-06	10%	1.890E-06	SpecLow	N/A
Min	1.830E-06	N	78	PctWithinSpec	N/A
Range	979.999E-09	Cp	N/A	PctDefSpec	N/A
StdDev	202.812E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8294	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	2.360E-06	Skew	-0.3029		
75%	2.340E-06	Kurtosis	-0.3404		
Median	2.290E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

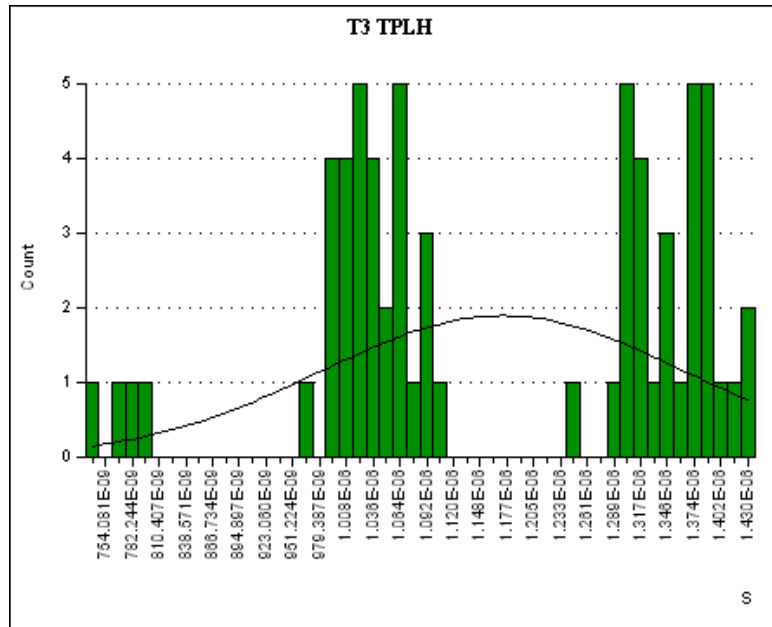
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.007, Test.Name=T3 TPLH



Statistics: (S)

Max	1.430E-06	25%	1.020E-06	SpecHigh	N/A
Mean	1.168E-06	10%	989.999E-09	SpecLow	N/A
Min	739.999E-09	N	64	PctWithinSpec	N/A
Range	689.999E-09	Cp	N/A	PctDefSpec	N/A
StdDev	189.642E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8855	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.390E-06	Skew	-0.2751		
75%	1.350E-06	Kurtosis	-0.9785		
Median	1.090E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

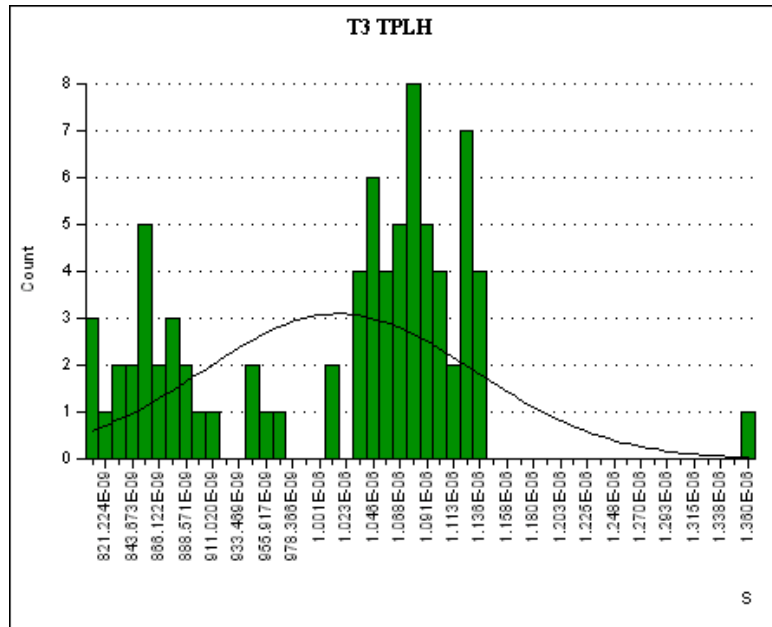
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.007, Test.Name=T3 TPLH



Statistics: (S)

Max	1.360E-06	25%	889.999E-09	SpecHigh	N/A
Mean	1.015E-06	10%	839.999E-09	SpecLow	N/A
Min	809.999E-09	N	78	PctWithinSpec	N/A
Range	549.999E-09	Cp	N/A	PctDefSpec	N/A
StdDev	112.788E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8751	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.120E-06	Skew	-0.2981		
75%	1.090E-06	Kurtosis	-0.2171		
Median	1.060E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

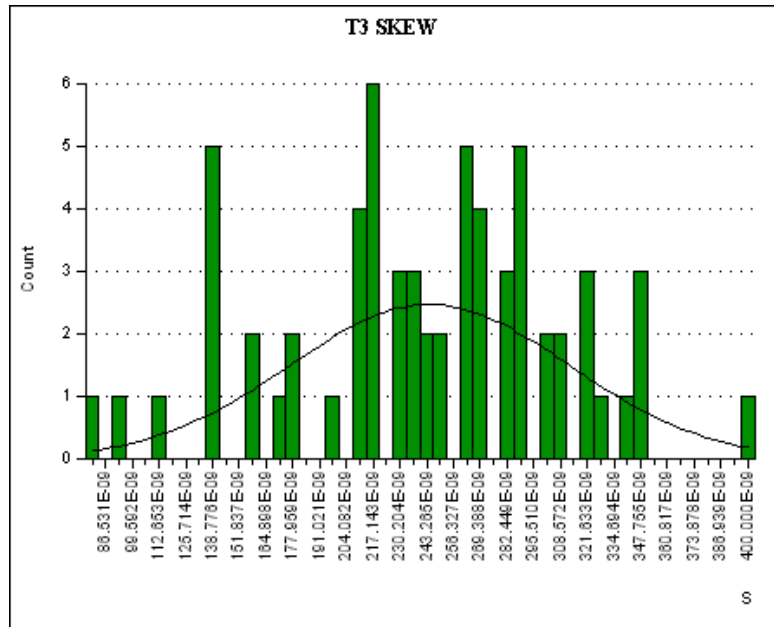
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.008, Test.Name=T3 SKEW



Statistics: (S)

Max	400.000E-09	25%	210.000E-09	SpecHigh	N/A
Mean	242.969E-09	10%	140.000E-09	SpecLow	N/A
Min	80.000E-09	N	64	PctWithinSpec	N/A
Range	320.000E-09	Cp	N/A	PctDefSpec	N/A
StdDev	67.440E-09	Cpl	N/A	NWithinSpec	N/A
W	0.9822	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.4825	Cpk	N/A		
90%	320.000E-09	Skew	-0.3101		
75%	290.000E-09	Kurtosis	-0.0764		
Median	245.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

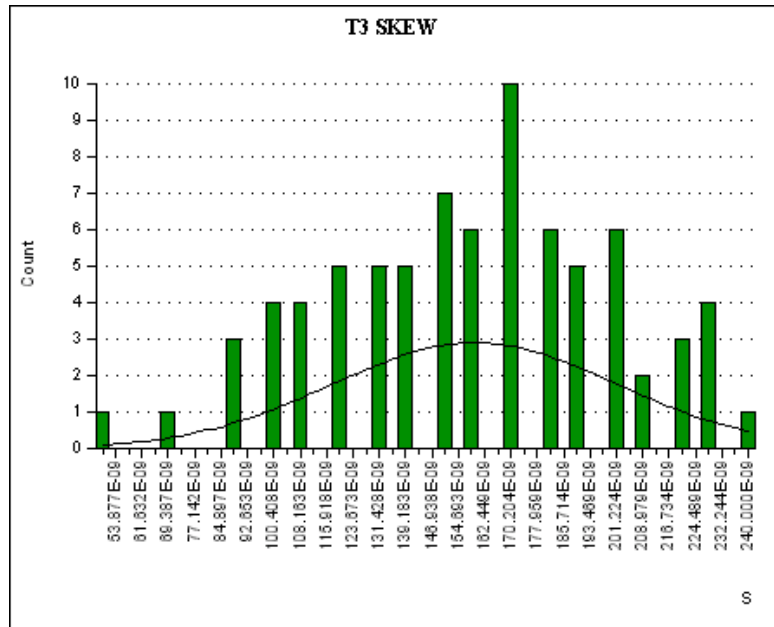
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.008, Test.Name=T3 SKEW



Statistics: (S)

Max	240.000E-09	25%	130.000E-09	SpecHigh	N/A
Mean	158.461E-09	10%	100.000E-09	SpecLow	N/A
Min	49.999E-09	N	78	PctWithinSpec	N/A
Range	190.000E-09	Cp	N/A	PctDefSpec	N/A
StdDev	41.656E-09	Cpl	N/A	NWithinSpec	N/A
W	0.9844	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.4610	Cpk	N/A		
90%	219.999E-09	Skew	-0.1805		
75%	190.000E-09	Kurtosis	-0.4184		
Median	160.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

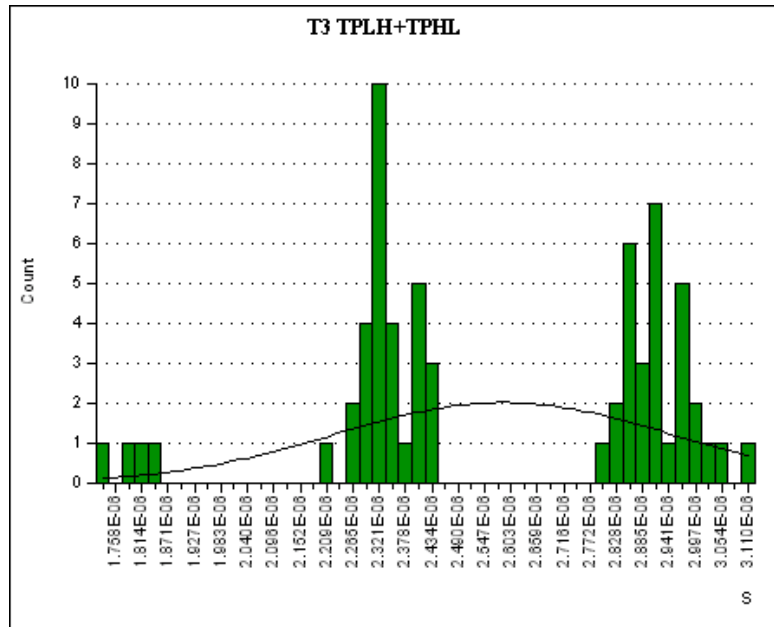
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.009, Test.Name=T3 TPLH+TPHL



Statistics: (S)

Max	3.110E-06	25%	2.320E-06	SpecHigh	N/A
Mean	2.578E-06	10%	2.270E-06	SpecLow	N/A
Min	1.730E-06	N	64	PctWithinSpec	N/A
Range	1.380E-06	Cp	N/A	PctDefSpec	N/A
StdDev	355.468E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8748	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	2.980E-06	Skew	-0.3994		
75%	2.905E-06	Kurtosis	-0.6955		
Median	2.430E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

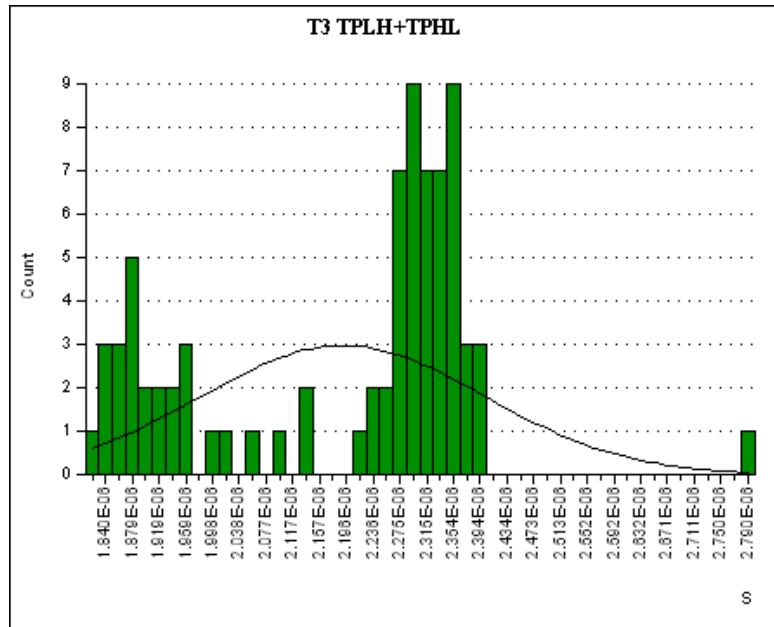
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.009, Test.Name=T3 TPLH+TPHL



Statistics: (S)

Max	2.790E-06	25%	1.960E-06	SpecHigh	N/A
Mean	2.188E-06	10%	1.870E-06	SpecLow	N/A
Min	1.820E-06	N	78	PctWithinSpec	N/A
Range	969.999E-09	Cp	N/A	PctDefSpec	N/A
StdDev	206.956E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8389	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	2.360E-06	Skew	-0.3926		
75%	2.330E-06	Kurtosis	-0.4651		
Median	2.285E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

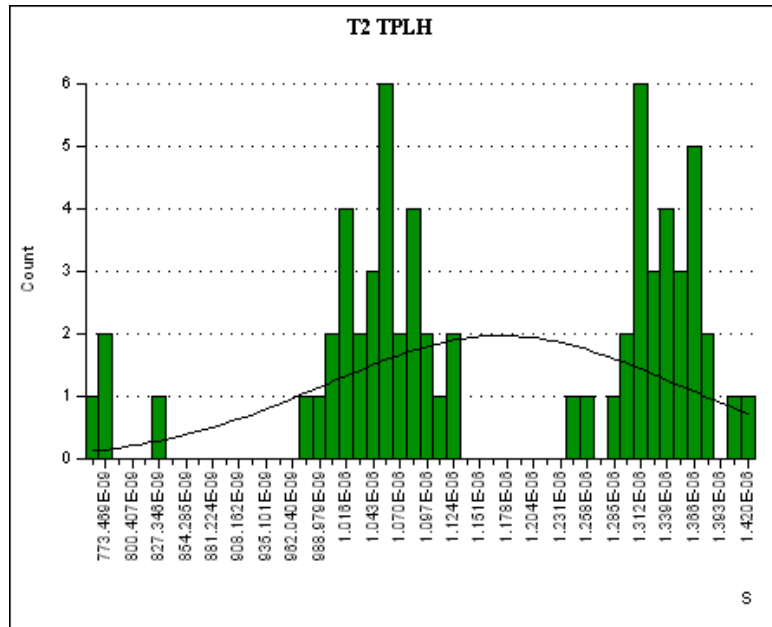
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.010, Test.Name=T2 TPLH



Statistics: (S)

Max	1.420E-06	25%	1.040E-06	SpecHigh	N/A
Mean	1.168E-06	10%	999.999E-09	SpecLow	N/A
Min	759.999E-09	N	64	PctWithinSpec	N/A
Range	659.999E-09	Cp	N/A	PctDefSpec	N/A
StdDev	174.418E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8940	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.360E-06	Skew	-0.3966		
75%	1.335E-06	Kurtosis	-0.7242		
Median	1.115E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

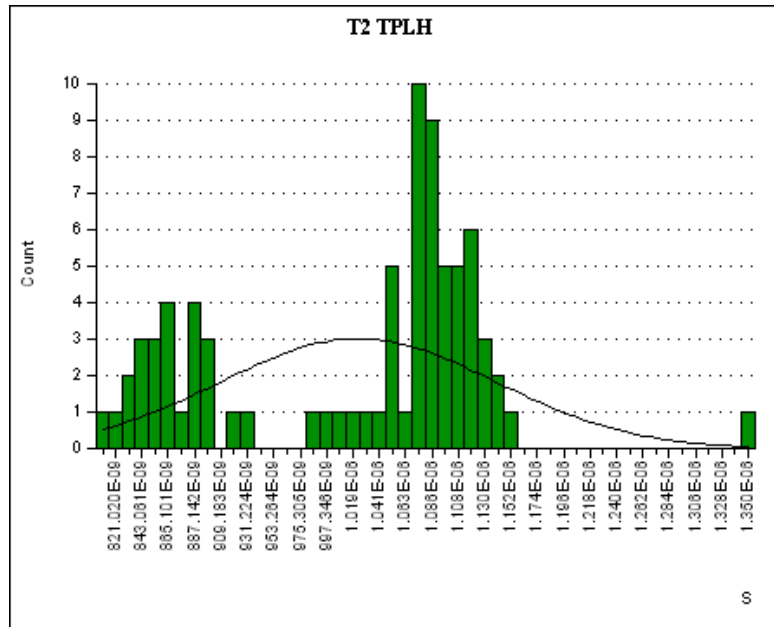
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.010, Test.Name=T2 TPLH



Statistics: (S)

Max	1.350E-06	25%	899.999E-09	SpecHigh	N/A
Mean	1.022E-06	10%	849.999E-09	SpecLow	N/A
Min	809.999E-09	N	78	PctWithinSpec	N/A
Range	539.999E-09	Cp	N/A	PctDefSpec	N/A
StdDev	113.664E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8659	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.120E-06	Skew	-0.3650		
75%	1.100E-06	Kurtosis	-0.4846		
Median	1.070E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

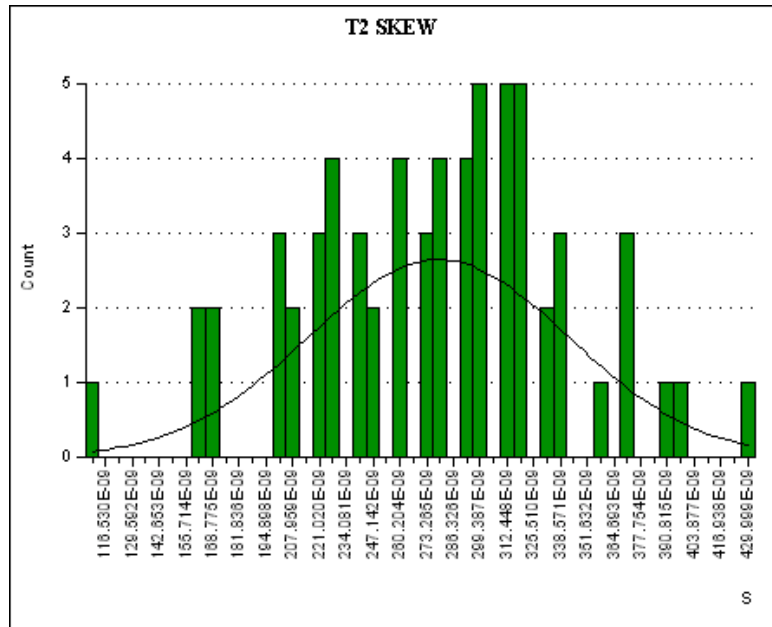
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.011, Test.Name=T2 SKEW



Statistics: (S)

Max	429.999E-09	25%	230.000E-09	SpecHigh	N/A
Mean	277.187E-09	10%	200.000E-09	SpecLow	N/A
Min	110.000E-09	N	64	PctWithinSpec	N/A
Range	319.999E-09	Cp	N/A	c	
StdDev	63.006E-09	Cpl	N/A	PctDefSpec	N/A
W	0.9921	Cpu	N/A	NWithinSpec	N/A
WpValue	0.9581	Cpk	N/A	NOutsideSpec	N/A
90%	360.000E-09	Skew	-0.1337		
75%	319.999E-09	Kurtosis	0.0863		
Median	280.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

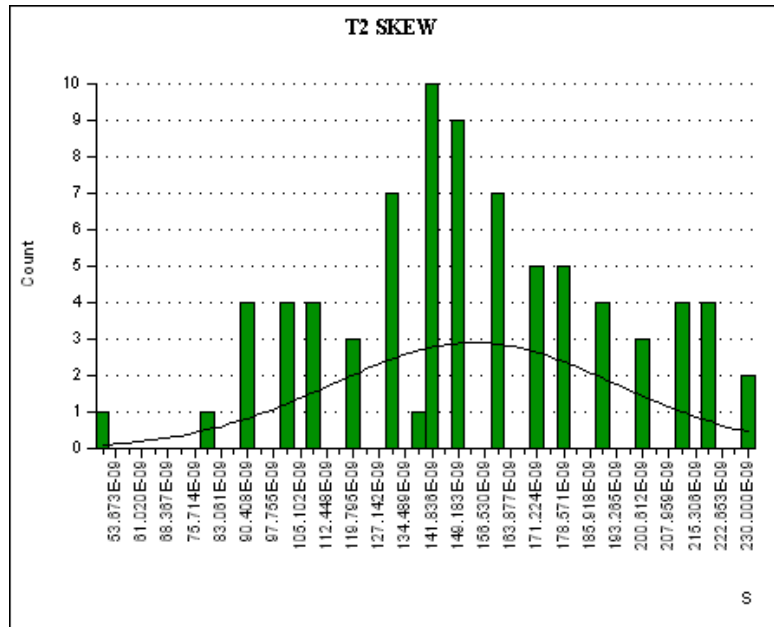
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.011, Test.Name=T2 SKEW



Statistics: (S)

Max	230.000E-09	25%	130.000E-09	SpecHigh	N/A
Mean	152.564E-09	10%	100.000E-09	SpecLow	N/A
Min	49.999E-09	N	78	PctWithinSpec	N/A
Range	180.000E-09	Cp	N/A	PctDefSpec	N/A
StdDev	39.425E-09	Cpl	N/A	NWithinSpec	N/A
W	0.9806	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.2791	Cpk	N/A		
90%	210.000E-09	Skew	0.0087		
75%	180.000E-09	Kurtosis	-0.3701		
Median	150.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

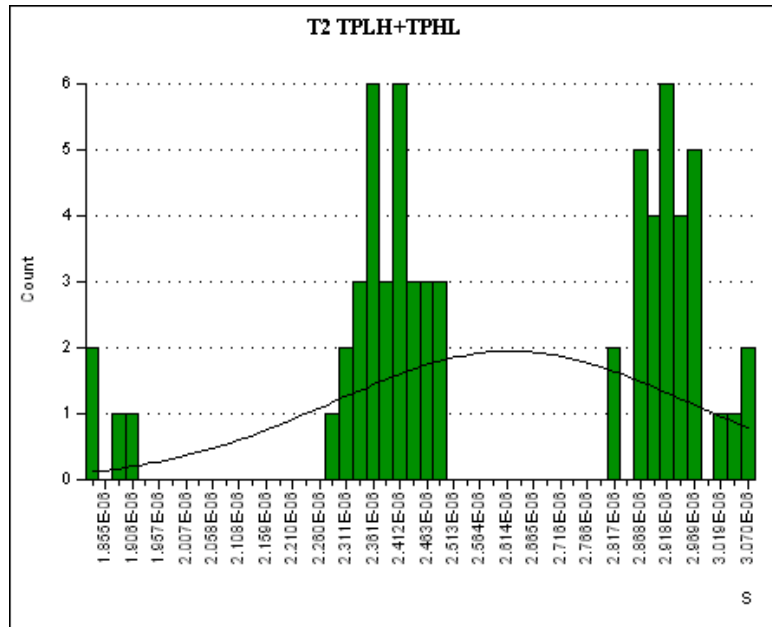
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.012, Test.Name=T2 TPLH+TPHL



Statistics: (S)

Max	3.070E-06	25%	2.375E-06	SpecHigh	N/A
Mean	2.613E-06	10%	2.300E-06	SpecLow	N/A
Min	1.830E-06	N	64	PctWithinSpec	N/A
Range	1.240E-06	Cp	N/A	PctDefSpec	N/A
StdDev	331.697E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8735	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	2.970E-06	Skew	-0.4447		
75%	2.930E-06	Kurtosis	-0.6219		
Median	2.495E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

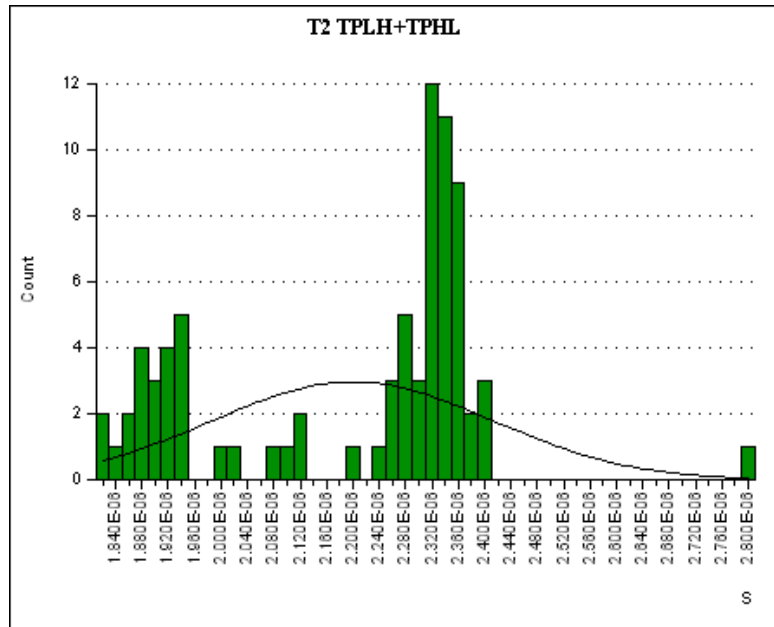
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.012, Test.Name=T2 TPLH+TPHL



Statistics: (S)

Max	2.800E-06	25%	1.940E-06	SpecHigh	N/A
Mean	2.196E-06	10%	1.870E-06	SpecLow	N/A
Min	1.820E-06	N	78	PctWithinSpec	N/A
Range	979.999E-09	Cp	N/A	PctDefSpec	N/A
StdDev	209.334E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8243	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	2.370E-06	Skew	-0.4024		
75%	2.340E-06	Kurtosis	-0.5289		
Median	2.300E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

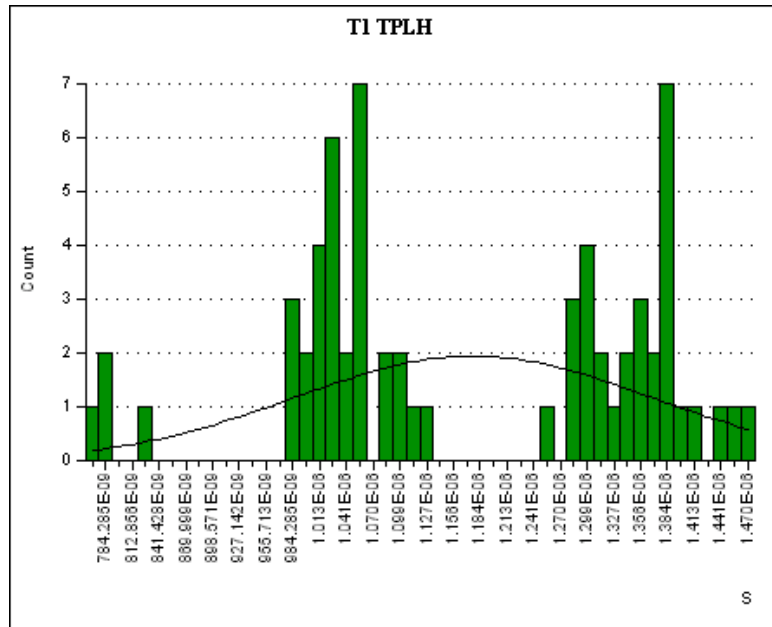
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.013, Test.Name=T1 TPLH



Statistics: (S)

Max	1.470E-06	25%	1.030E-06	SpecHigh	N/A
Mean	1.173E-06	10%	989.999E-09	SpecLow	N/A
Min	769.999E-09	N	64	PctWithinSpec	N/A
Range	699.999E-09	Cp	N/A	PctDefSpec	N/A
StdDev	187.477E-09	Cpl	N/A	NWithinSpec	N/A
W	0.9060	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0001	Cpk	N/A		
90%	1.390E-06	Skew	-0.2046		
75%	1.350E-06	Kurtosis	-1.0192		
Median	1.110E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

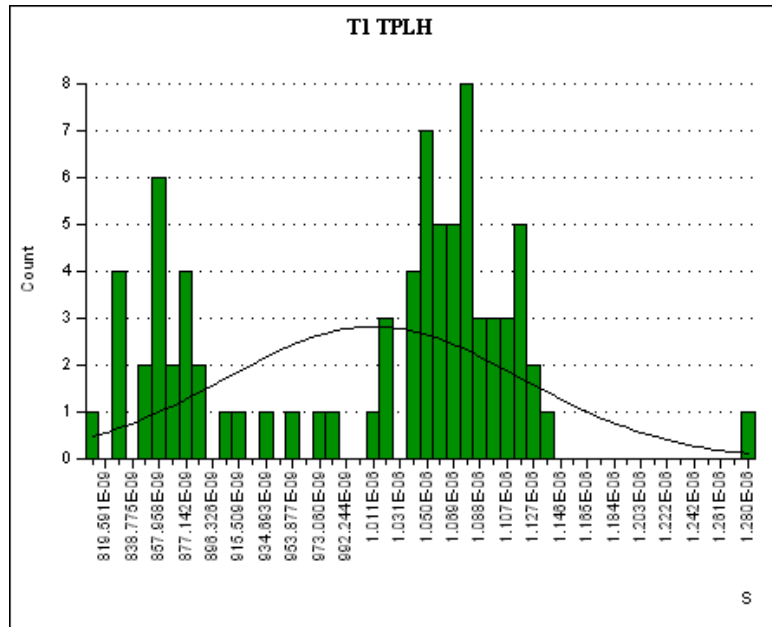
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.013, Test.Name=T1 TPLH



Statistics: (S)

Max	1.280E-06	25%	889.999E-09	SpecHigh	N/A
Mean	1.009E-06	10%	859.999E-09	SpecLow	N/A
Min	809.999E-09	N	78	PctWithinSpec	N/A
Range	469.999E-09	Cp	N/A	PctDefSpec	N/A
StdDev	105.644E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8871	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.120E-06	Skew	-0.3957		
75%	1.080E-06	Kurtosis	-0.8327		
Median	1.050E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

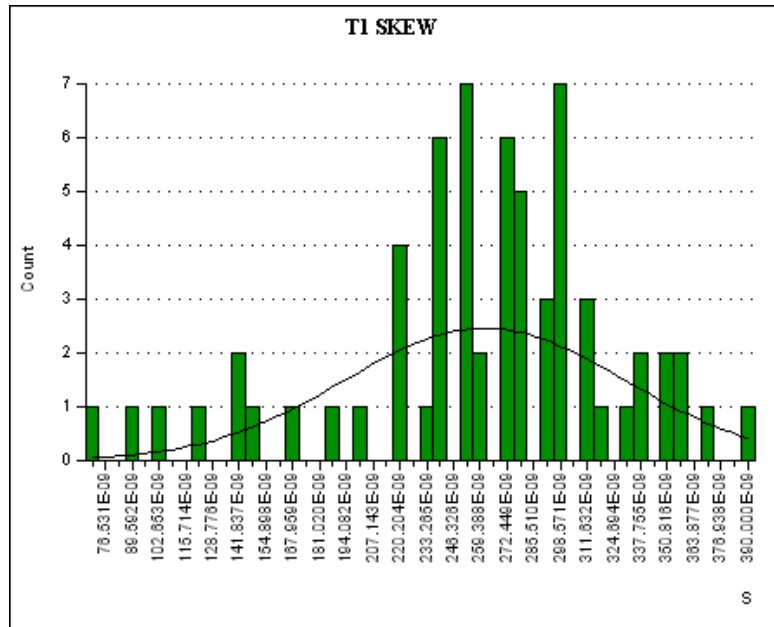
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.014, Test.Name=T1 SKEW



Statistics: (S)

Max	390.000E-09	25%	239.999E-09	SpecHigh	N/A
Mean	259.687E-09	10%	150.000E-09	SpecLow	N/A
Min	70.000E-09	N	64	PctWithinSpec	N/A
Range	319.999E-09	Cp	N/A	c	
StdDev	67.682E-09	Cpl	N/A	PctDefSpec	N/A
W	0.9439	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0058	Cpk	N/A	NOutsideSpec	N/A
90%	339.999E-09	Skew	-0.8052		
75%	300.000E-09	Kurtosis	0.8093		
Median	270.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

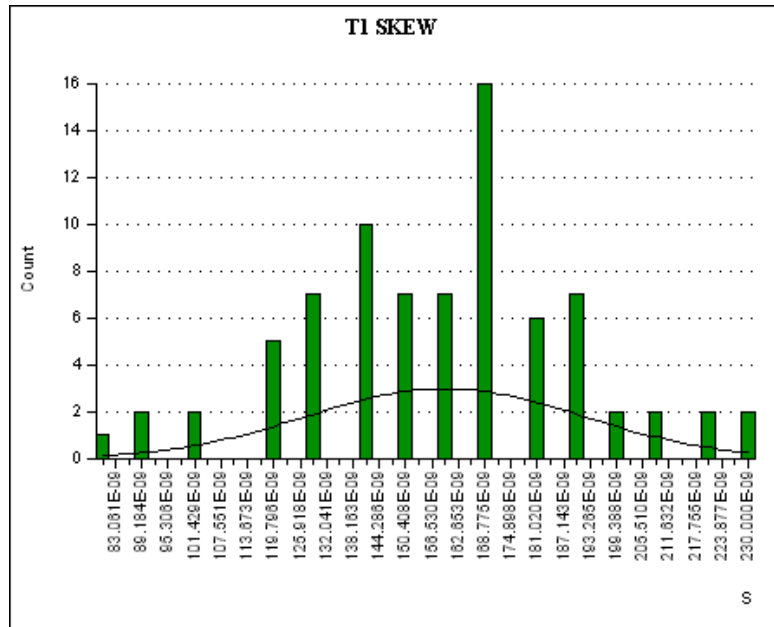
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.014, Test.Name=T1 SKEW



Statistics: (S)

Max	230.000E-09	25%	139.999E-09	SpecHigh	N/A
Mean	158.846E-09	10%	120.000E-09	SpecLow	N/A
Min	80.000E-09	N	78	PctWithinSpec	N/A
Range	150.000E-09	Cp	N/A	c	
StdDev	31.786E-09	Cpl	N/A	PctDefSpec	N/A
W	0.9804	Cpu	N/A	NWithinSpec	N/A
WpValue	0.2724	Cpk	N/A	NOutsideSpec	N/A
90%	200.000E-09	Skew	-0.0862		
75%	180.000E-09	Kurtosis	0.0677		
Median	160.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

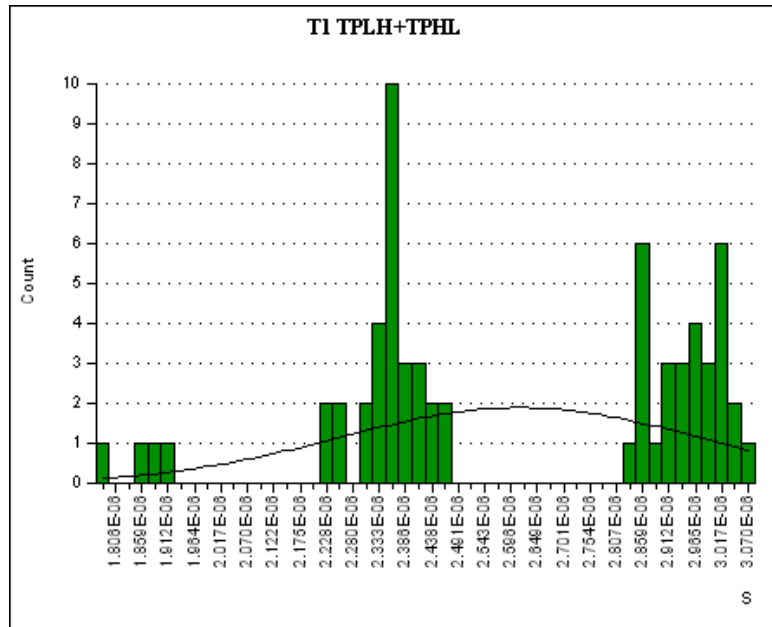
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.015, Test.Name=T1 TPLH+TPHL



Statistics: (S)

Max	3.070E-06	25%	2.360E-06	SpecHigh	N/A
Mean	2.605E-06	10%	2.250E-06	SpecLow	N/A
Min	1.780E-06	N	64	PctWithinSpec	N/A
Range	1.290E-06	Cp	N/A	c	
StdDev	354.678E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8713	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	3.020E-06	Skew	-0.3090		
75%	2.955E-06	Kurtosis	-0.9697		
Median	2.455E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

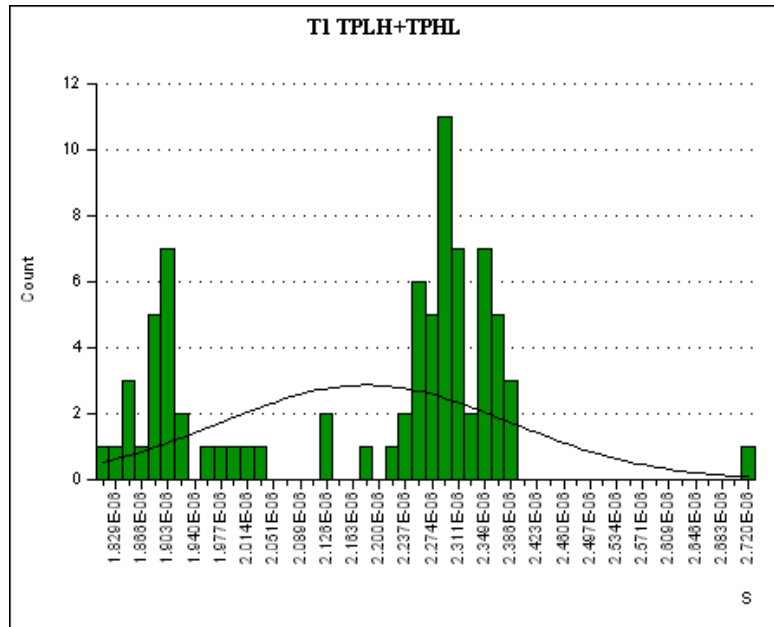
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.015, Test.Name=T1 TPLH+TPHL



Statistics: (S)

Max	2.720E-06	25%	1.930E-06	SpecHigh	N/A
Mean	2.178E-06	10%	1.880E-06	SpecLow	N/A
Min	1.810E-06	N	78	PctWithinSpec	N/A
Range	909.999E-09	Cp	N/A	PctDefSpec	N/A
StdDev	201.318E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8429	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	2.360E-06	Skew	-0.4240		
75%	2.320E-06	Kurtosis	-0.7653		
Median	2.270E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

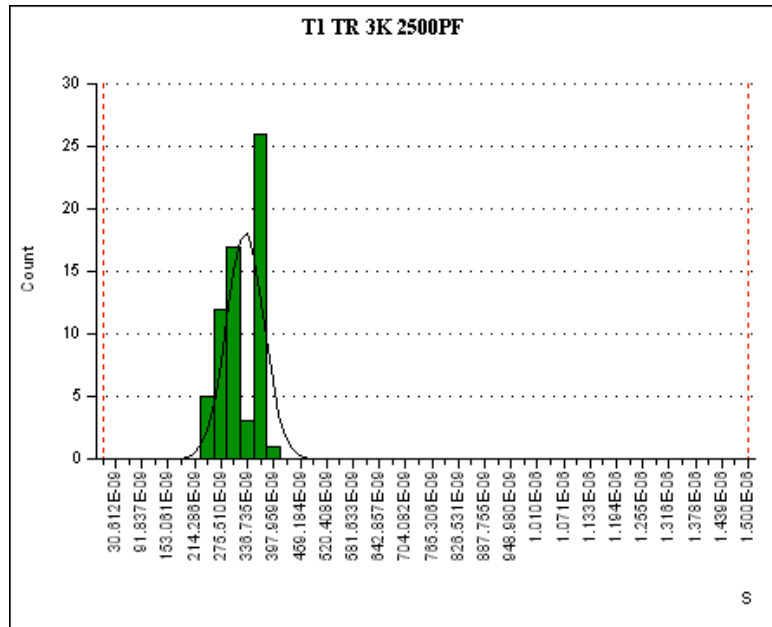
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=10.000, Test.Name=T1 TR 3K 2500PF



Statistics: (S)

Max	390.000E-09	25%	290.000E-09	SpecHigh	1.500E-06
Mean	326.875E-09	10%	280.000E-09	SpecLow	0
Min	230.000E-09	N	64	PctWithinSpec	100.00
Range	160.000E-09	Cp	>4.0000	PctDefSpec	0
StdDev	43.016E-09	Cpl	2.5330	NWithinSpec	64
W	0.9054	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0001	Cpk	2.5330		
90%	380.000E-09	Skew	-0.2641		
75%	370.000E-09	Kurtosis	-1.1144		
Median	315.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

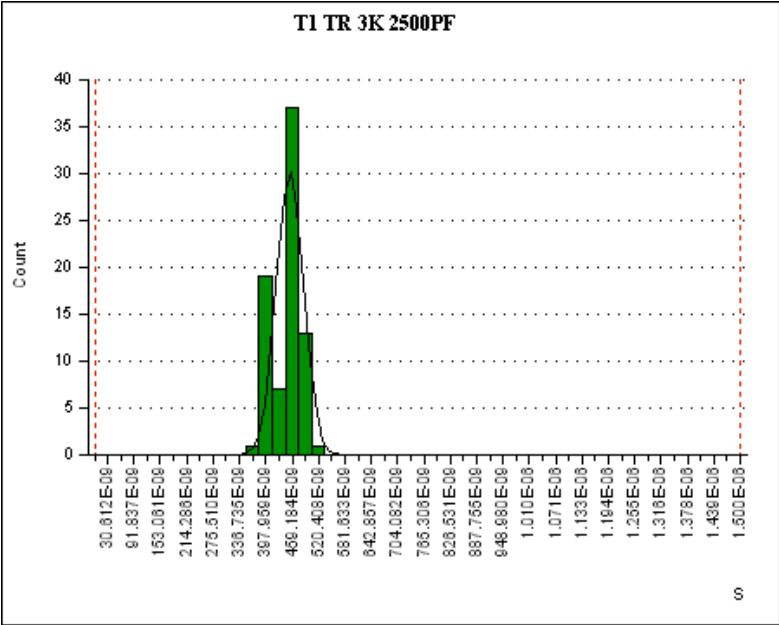
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=10.000, Test.Name=T1 TR 3K 2500PF



Statistics: (S)

Max	520.000E-09	25%	410.000E-09	SpecHigh	1.500E-06
Mean	448.333E-09	10%	400.000E-09	SpecLow	0
Min	380.000E-09	N	78	PctWithinSpec	100.00
Range	140.000E-09	Cp	>4.0000	c	
StdDev	31.475E-09	Cpl	>4.0000	PctDefSpec	0
W	0.9020	Cpu	>4.0000	NWithinSpec	78
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	480.000E-09	Skew	-0.4912		
75%	470.000E-09	Kurtosis	-0.8267		
Median	460.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

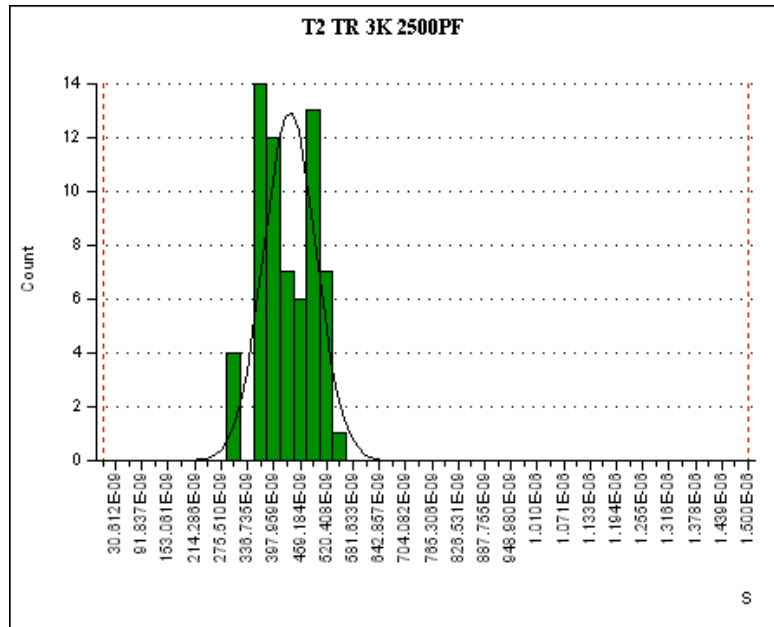
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=10.001, Test.Name=T2 TR 3K 2500PF



Statistics: (S)

Max	539.999E-09	25%	380.000E-09	SpecHigh	1.500E-06
Mean	430.000E-09	10%	369.999E-09	SpecLow	0
Min	310.000E-09	N	64	PctWithinSpec	100.00
Range	230.000E-09	Cp	>4.0000	c	
StdDev	60.501E-09	Cpl	2.3691	PctDefSpec	0
W	0.9501	Cpu	>4.0000	NWithinSpec	64
WpValue	0.0116	Cpk	2.3691	NOutsideSpec	0
90%	509.999E-09	Skew	-0.0115		
75%	490.000E-09	Kurtosis	-1.0122		
Median	420.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

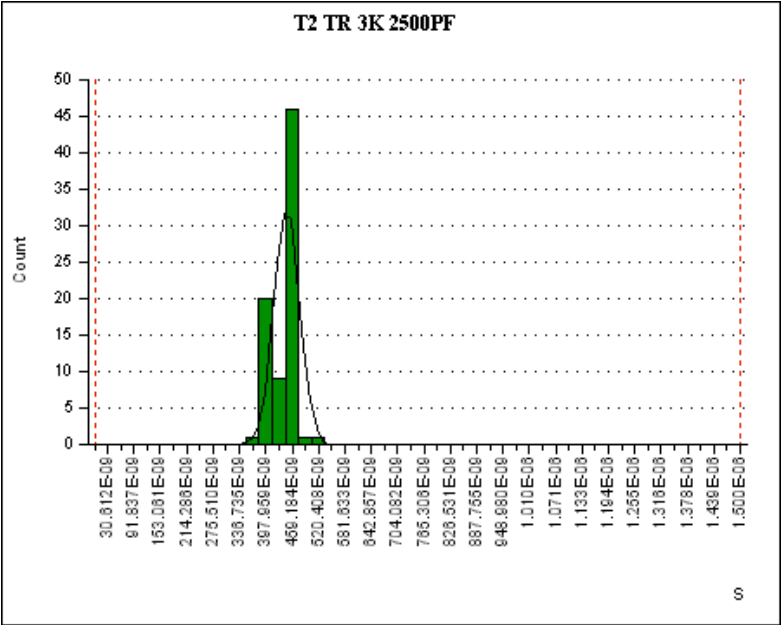
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=10.001, Test.Name=T2 TR 3K 2500PF



Statistics: (S)

Max	520.000E-09	25%	410.000E-09	SpecHigh	1.500E-06
Mean	441.025E-09	10%	400.000E-09	SpecLow	0
Min	370.000E-09	N	78	PctWithinSpec	100.00
Range	150.000E-09	Cp	>4.0000	c	
StdDev	29.347E-09	Cpl	>4.0000	PctDefSpec	0
W	0.8937	Cpu	>4.0000	NWithinSpec	78
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	470.000E-09	Skew	-0.4578		
75%	460.000E-09	Kurtosis	-0.4098		
Median	450.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

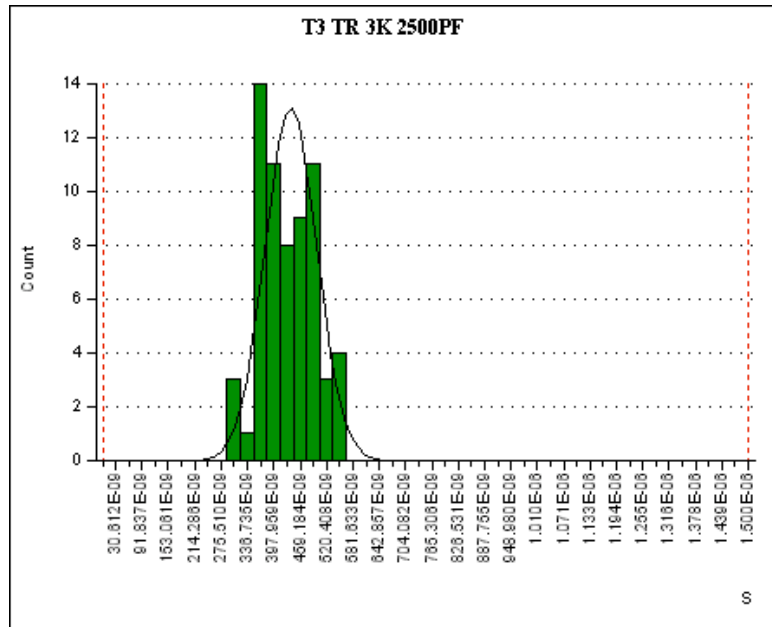
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=10.002, Test.Name=T3 TR 3K 2500PF



Statistics: (S)

Max	539.999E-09	25%	380.000E-09	SpecHigh	1.500E-06
Mean	432.187E-09	10%	369.999E-09	SpecLow	0
Min	320.000E-09	N	64	PctWithinSpec	100.00
Range	220.000E-09	Cp	>4.0000	PctDefSpec	0
StdDev	59.694E-09	Cpl	2.4133	NWithinSpec	64
W	0.9554	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0214	Cpk	2.4133		
90%	509.999E-09	Skew	0.1103		
75%	490.000E-09	Kurtosis	-0.9817		
Median	420.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

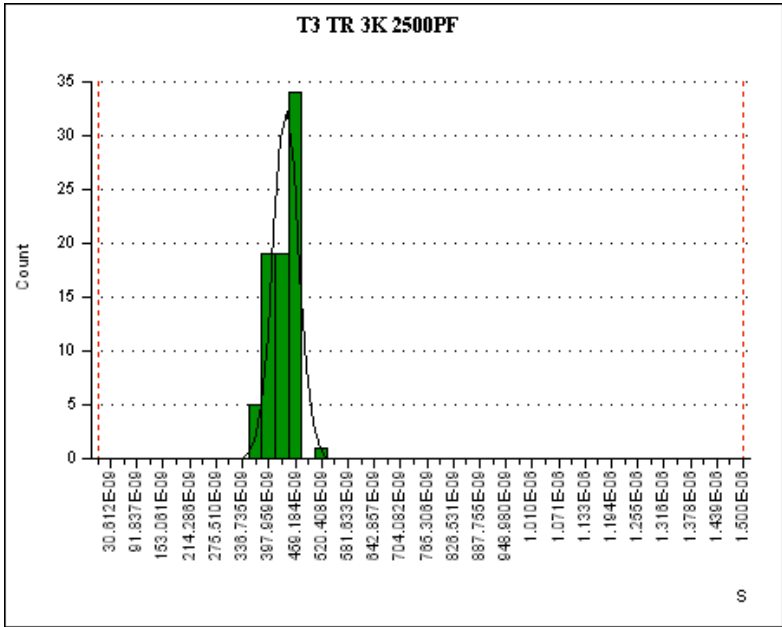
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=10.002, Test.Name=T3 TR 3K 2500PF



Statistics: (S)

Max	510.000E-09	25%	400.000E-09	SpecHigh	1.500E-06
Mean	432.051E-09	10%	390.000E-09	SpecLow	0
Min	370.000E-09	N	78	PctWithinSpec	100.00
Range	140.000E-09	Cp	>4.0000	c	
StdDev	29.426E-09	Cpl	>4.0000	PctDefSpec	0
W	0.8872	Cpu	>4.0000	NWithinSpec	78
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	460.000E-09	Skew	-0.4263		
75%	450.000E-09	Kurtosis	-0.5958		
Median	440.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

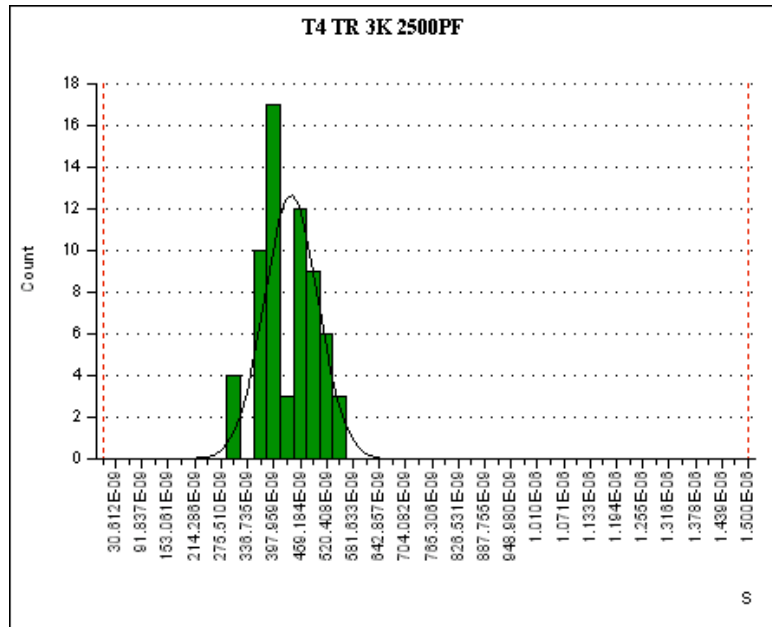
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=10.003, Test.Name=T4 TR 3K 2500PF



Statistics: (S)

Max	549.999E-09	25%	390.000E-09	SpecHigh	1.500E-06
Mean	432.812E-09	10%	360.000E-09	SpecLow	0
Min	310.000E-09	N	64	PctWithinSpec	100.00
Range	240.000E-09	Cp	>4.0000	PctDefSpec	0
StdDev	61.810E-09	Cpl	2.3341	NWithinSpec	64
W	0.9600	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0366	Cpk	2.3341		
90%	520.000E-09	Skew	0.0405		
75%	485.000E-09	Kurtosis	-0.8382		
Median	424.999E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

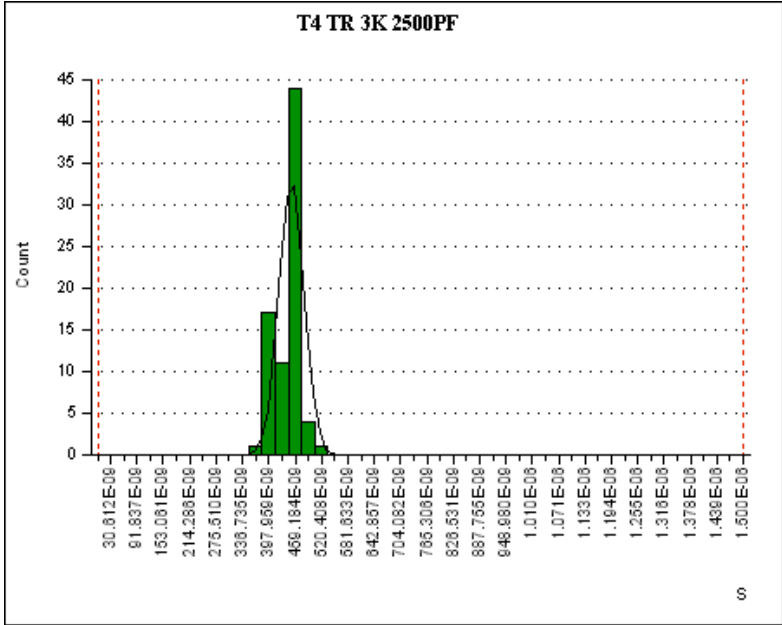
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=10.003, Test.Name=T4 TR 3K 2500PF



Statistics: (S)

Max	510.000E-09	25%	420.000E-09	SpecHigh	1.500E-06
Mean	444.871E-09	10%	400.000E-09	SpecLow	0
Min	380.000E-09	N	78	PctWithinSpec	100.00
Range	130.000E-09	Cp	>4.0000	c	
StdDev	28.953E-09	Cpl	>4.0000	PctDefSpec	0
W	0.9004	Cpu	>4.0000	NWithinSpec	78
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	470.000E-09	Skew	-0.5318		
75%	470.000E-09	Kurtosis	-0.7647		
Median	460.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

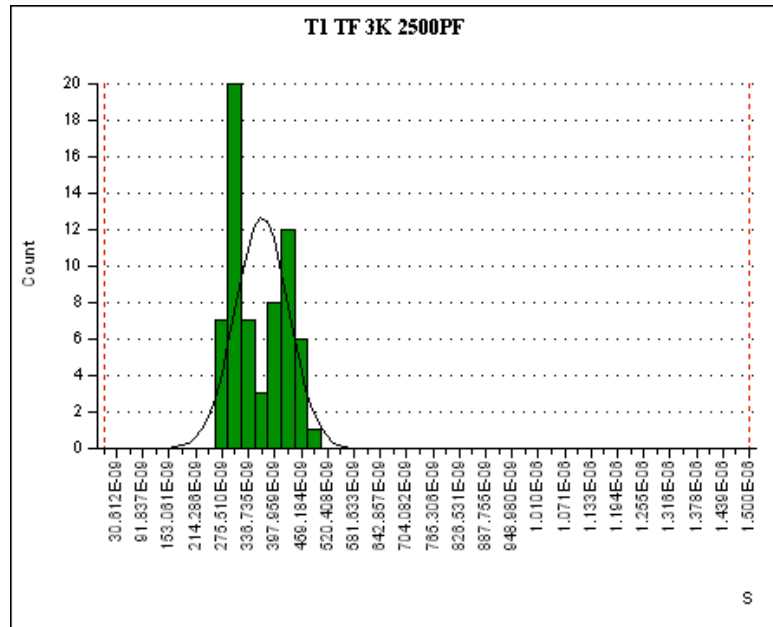
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=10.004, Test.Name=T1 TF 3K 2500PF



Statistics: (S)

Max	480.000E-09	25%	310.000E-09	SpecHigh	1.500E-06
Mean	363.125E-09	10%	290.000E-09	SpecLow	0
Min	270.000E-09	N	64	PctWithinSpec	100.00
Range	210.000E-09	Cp	>4.0000	c	
StdDev	61.692E-09	Cpl	1.9620	PctDefSpec	0
W	0.9102	Cpu	>4.0000	NWithinSpec	64
WpValue	0.0002	Cpk	1.9620	NOutsideSpec	0
90%	450.000E-09	Skew	0.2824		
75%	420.000E-09	Kurtosis	-1.3936		
Median	345.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

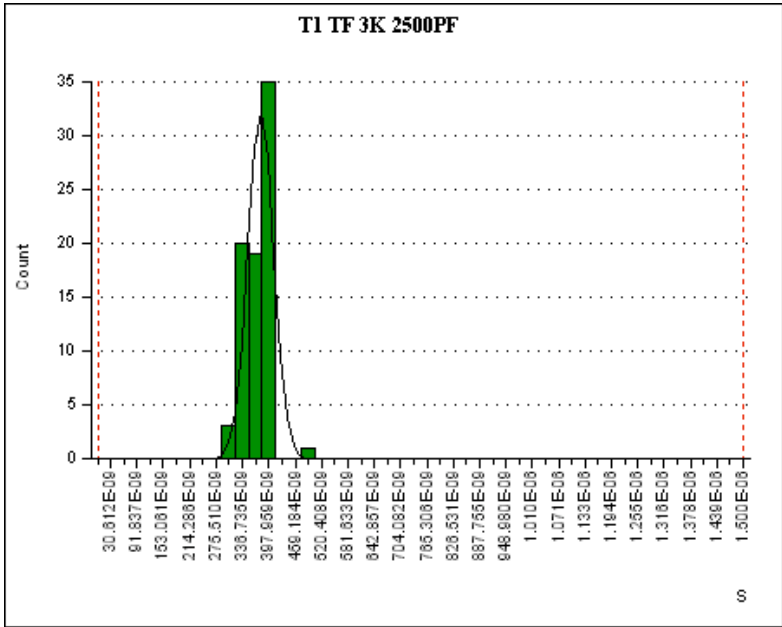
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=10.004, Test.Name=T1 TF 3K 2500PF



Statistics: (S)

Max	490.000E-09	25%	340.000E-09	SpecHigh	1.500E-06
Mean	373.974E-09	10%	330.000E-09	SpecLow	0
Min	320.000E-09	N	78	PctWithinSpec	100.00
Range	170.000E-09	Cp	>4.0000	c	
StdDev	29.513E-09	Cpl	>4.0000	PctDefSpec	0
W	0.8888	Cpu	>4.0000	NWithinSpec	78
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	400.000E-09	Skew	0.2833		
75%	390.000E-09	Kurtosis	1.6393		
Median	380.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

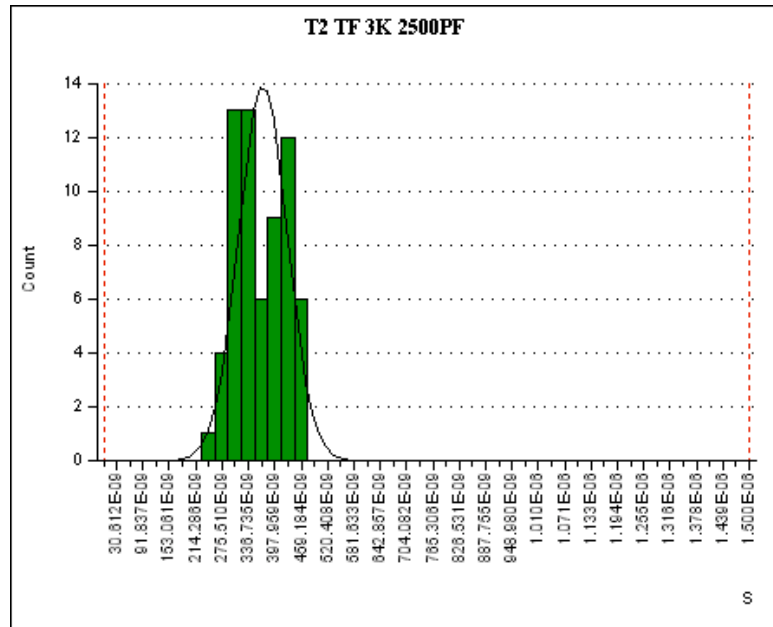
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=10.005, Test.Name=T2 TF 3K 2500PF



Statistics: (S)

Max	470.000E-09	25%	315.000E-09	SpecHigh	1.500E-06
Mean	365.625E-09	10%	300.000E-09	SpecLow	0
Min	260.000E-09	N	64	PctWithinSpec	100.00
Range	210.000E-09	Cp	>4.0000	PctDefSpec	0
StdDev	56.171E-09	Cpl	2.1697	NWithinSpec	64
W	0.9484	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0096	Cpk	2.1697		
90%	440.000E-09	Skew	0.1637		
75%	420.000E-09	Kurtosis	-1.1240		
Median	365.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

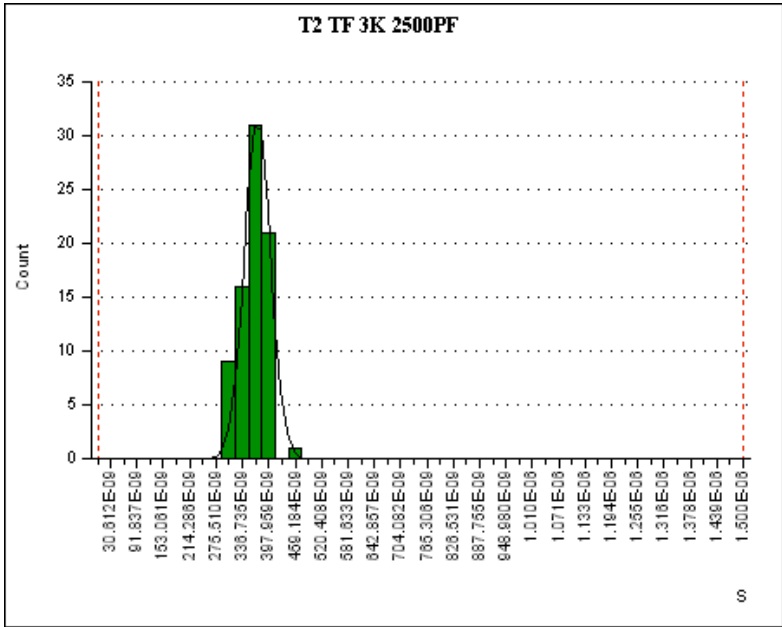
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=10.005, Test.Name=T2 TF 3K 2500PF



Statistics: (S)

Max	470.000E-09	25%	340.000E-09	SpecHigh	1.500E-06
Mean	366.410E-09	10%	320.000E-09	SpecLow	0
Min	300.000E-09	N	78	PctWithinSpec	100.00
Range	170.000E-09	Cp	>4.0000	c	
StdDev	30.064E-09	Cpl	>4.0000	PctDefSpec	0
W	0.9007	Cpu	>4.0000	NWithinSpec	78
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	390.000E-09	Skew	-0.1152		
75%	390.000E-09	Kurtosis	0.6243		
Median	380.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

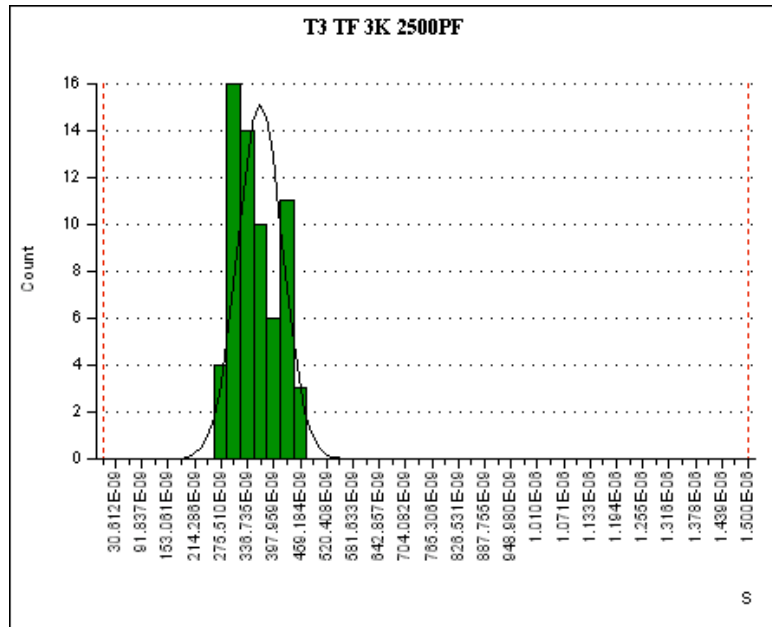
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=10.006, Test.Name=T3 TF 3K 2500PF



Statistics: (S)

Max	470.000E-09	25%	320.000E-09	SpecHigh	1.500E-06
Mean	361.406E-09	10%	300.000E-09	SpecLow	0
Min	280.000E-09	N	64	PctWithinSpec	100.00
Range	190.000E-09	Cp	>4.0000	PctDefSpec	0
StdDev	51.666E-09	Cpl	2.3317	NWithinSpec	64
W	0.9376	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0029	Cpk	2.3317		
90%	430.000E-09	Skew	0.4343		
75%	400.000E-09	Kurtosis	-0.8778		
Median	345.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

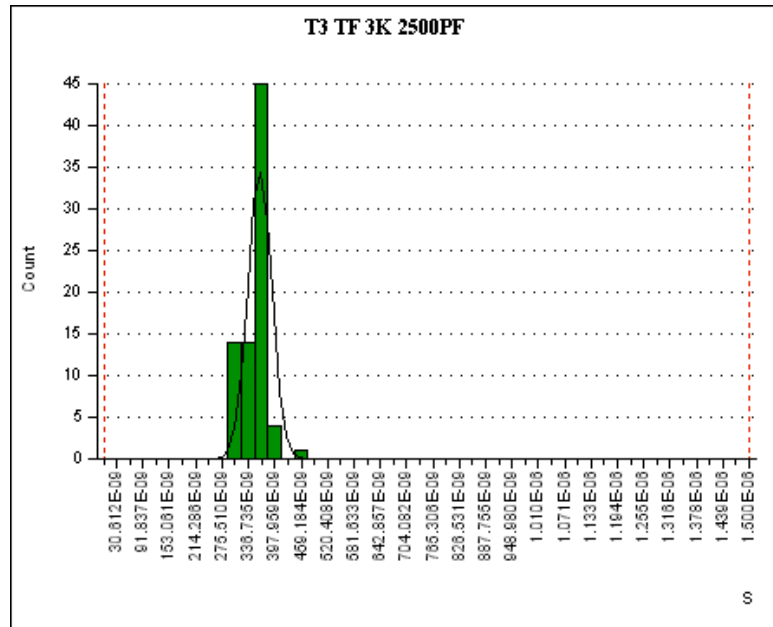
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=10.006, Test.Name=T3 TF 3K 2500PF



Statistics: (S)

Max	450.000E-09	25%	330.000E-09	SpecHigh	1.500E-06
Mean	357.948E-09	10%	320.000E-09	SpecLow	0
Min	310.000E-09	N	78	PctWithinSpec	100.00
Range	140.000E-09	Cp	>4.0000	PctDefSpec	0
StdDev	27.651E-09	Cpl	>4.0000	NWithinSpec	78
W	0.8829	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	380.000E-09	Skew	-0.1141		
75%	380.000E-09	Kurtosis	0.1955		
Median	370.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

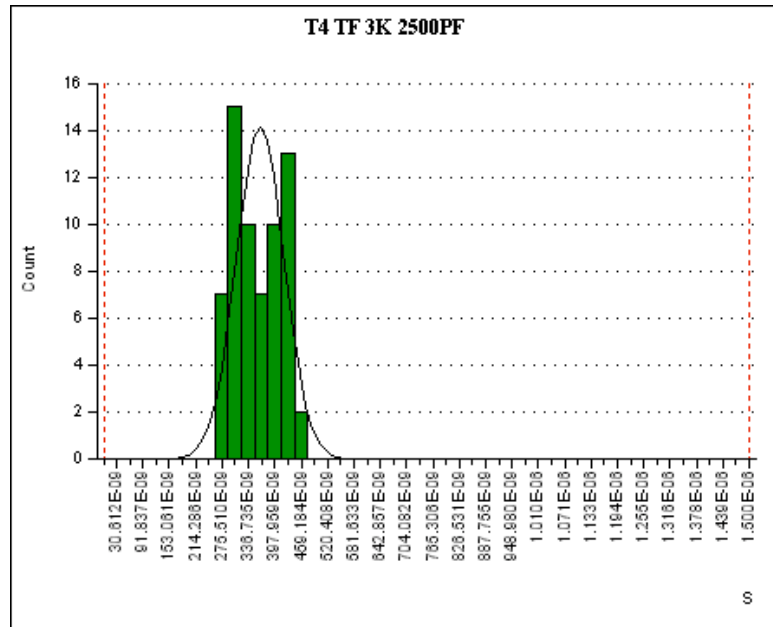
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=10.007, Test.Name=T4 TF 3K 2500PF



Statistics: (S)

Max	470.000E-09	25%	310.000E-09	SpecHigh	1.500E-06
Mean	359.062E-09	10%	290.000E-09	SpecLow	0
Min	270.000E-09	N	64	PctWithinSpec	100.00
Range	200.000E-09	Cp	>4.0000	PctDefSpec	0
StdDev	55.168E-09	Cpl	2.1695	NWithinSpec	64
W	0.9323	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0017	Cpk	2.1695		
90%	430.000E-09	Skew	0.1809		
75%	410.000E-09	Kurtosis	-1.3060		
Median	355.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

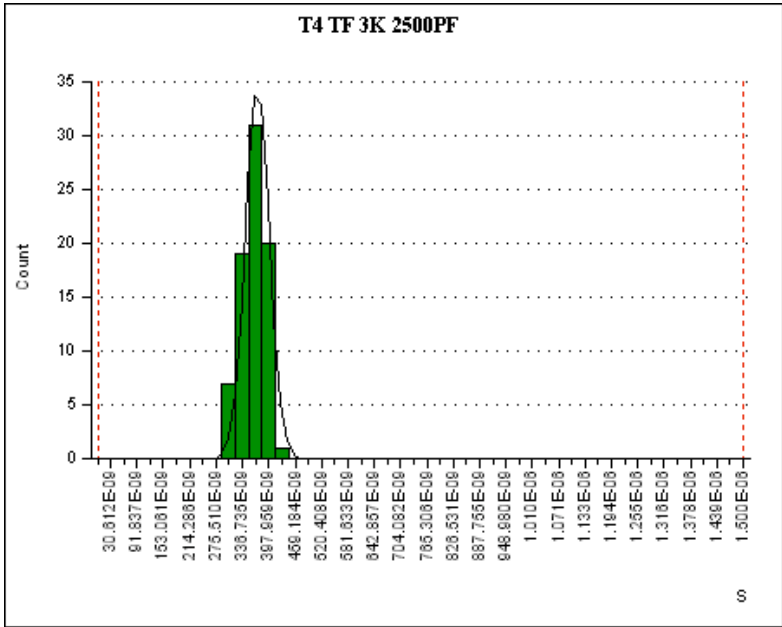
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=10.007, Test.Name=T4 TF 3K 2500PF



Statistics: (S)

Max	430.000E-09	25%	340.000E-09	SpecHigh	1.500E-06
Mean	366.282E-09	10%	330.000E-09	SpecLow	0
Min	310.000E-09	N	78	PctWithinSpec	100.00
Range	120.000E-09	Cp	>4.0000	c	
StdDev	27.592E-09	Cpl	>4.0000	PctDefSpec	0
W	0.9287	Cpu	>4.0000	NWithinSpec	78
WpValue	0.0003	Cpk	>4.0000	NOutsideSpec	0
90%	400.000E-09	Skew	-0.3738		
75%	390.000E-09	Kurtosis	-0.8094		
Median	380.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

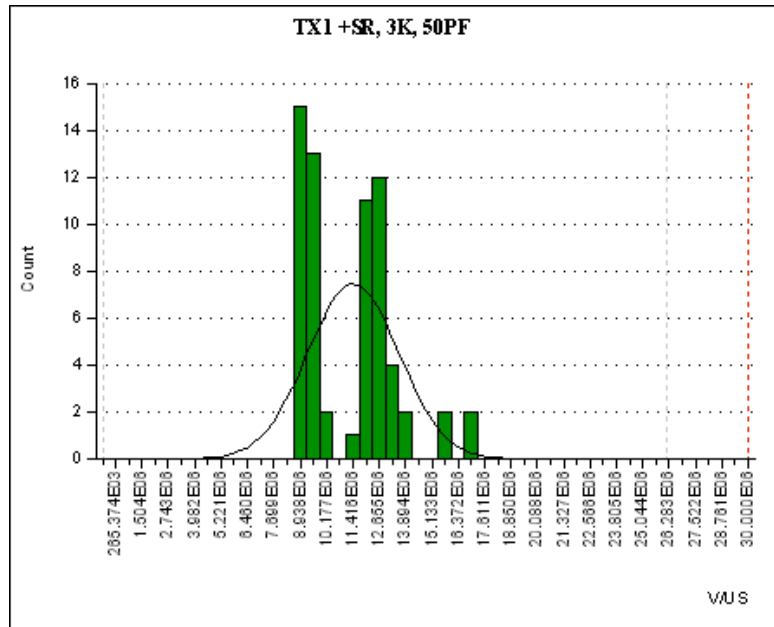
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=11.000, Test.Name=TX1 +SR, 3K, 50PF



Statistics: (V/U S)

Max	17.143E06	25%	9.375E06	SpecHigh	30.000E06
Mean	11.285E06	10%	9.091E06	SpecLow	N/A
Min	8.824E06	N	64	PctWithinSpec	100.00
Range	8.319E06	Cp	N/A	PctDefSpec	0
StdDev	2.117E06	Cpl	N/A	NWithinSpec	64
W	0.8707	Cpu	2.9463	NOutsideSpec	0
WpValue	0.0000	Cpk	2.9463		
90%	13.333E06	Skew	0.7608		
75%	12.500E06	Kurtosis	0.2067		
Median	11.765E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

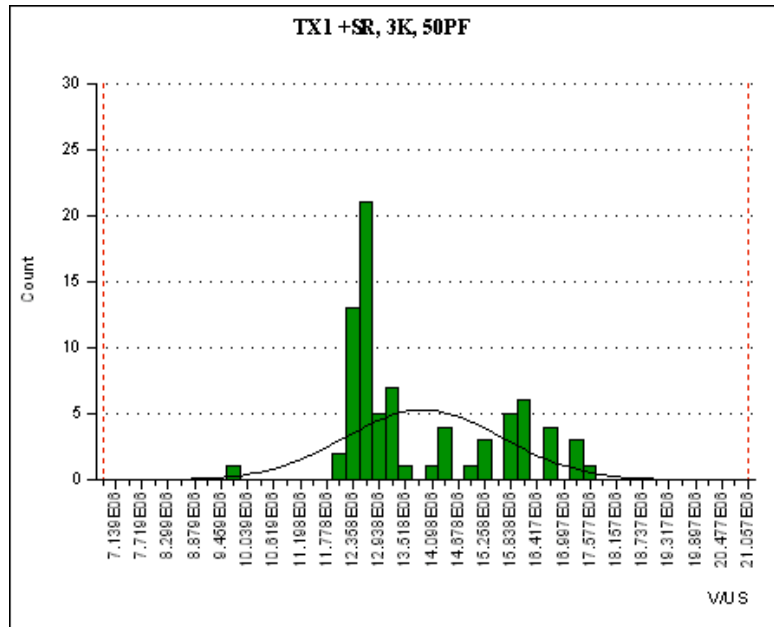
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
26.170E06	-354.097E03	100.00	0	64	0

Plot limits applied

NOutsidePlot

0

Test.Number=11.000, Test.Name=TX1 +SR, 3K, 50PF



Statistics: (V/US)

Max	17.647E06	25%	12.766E06	SpecHigh	21.057E06
Mean	13.837E06	10%	12.245E06	SpecLow	6.849E06
Min	9.836E06	N	78	PctWithinSpec	100.00
Range	7.811E06	Cp	1.3969	c	
StdDev	1.695E06	Cpl	1.3742	PctDefSpec	0
W	0.8614	Cpu	1.4196	NWithinSpec	78
WpValue	0.0000	Cpk	1.3742	NOutsideSpec	0
90%	16.667E06	Skew	0.6529		
75%	15.385E06	Kurtosis	-0.6050		
Median	13.043E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

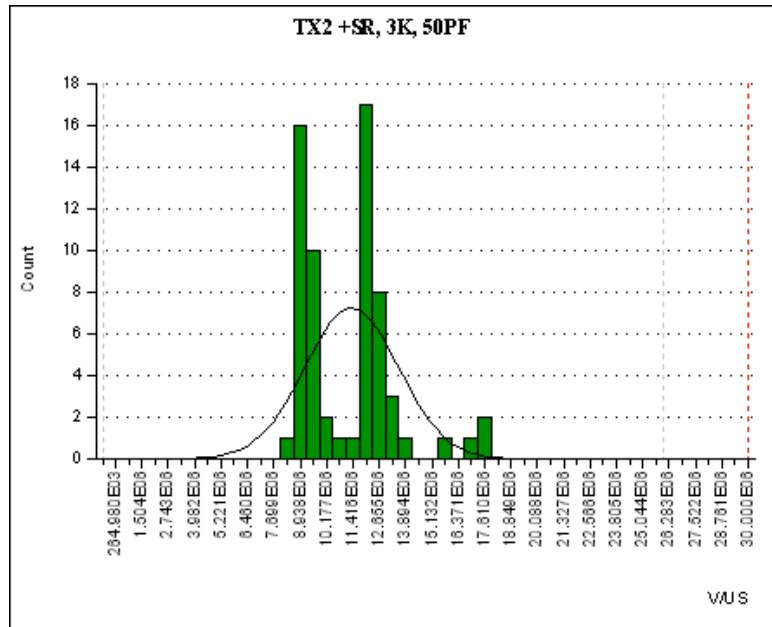
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=11.001, Test.Name=TX2 +SR, 3K, 50PF



Statistics: (V/US)

Max	17.647E06	25%	9.231E06	SpecHigh	30.000E06
Mean	11.222E06	10%	8.955E06	SpecLow	N/A
Min	8.571E06	N	64	PctWithinSpec	100.00
Range	9.076E06	Cp	N/A	c	
StdDev	2.190E06	Cpl	N/A	PctDefSpec	0
W	0.8560	Cpu	2.8580	NWithinSpec	64
WpValue	0.0000	Cpk	2.8580	NOutsideSpec	0
90%	13.043E06	Skew	1.0199		
75%	12.372E06	Kurtosis	1.1923		
Median	11.882E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

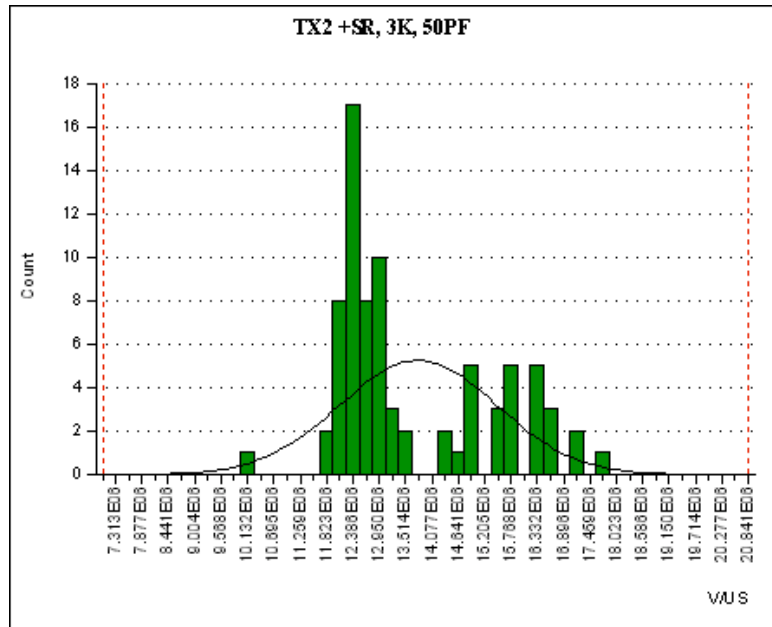
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
26.004E06	-354.500E03	100.00	0	64	0

Plot limits applied

NOutsidePlot

0

Test.Number=11.001, Test.Name=TX2 +SR, 3K, 50PF



Statistics: (V/US)

Max	17.647E06	25%	12.500E06	SpecHigh	20.841E06
Mean	13.714E06	10%	12.245E06	SpecLow	7.032E06
Min	10.000E06	N	78	PctWithinSpec	100.00
Range	7.647E06	Cp	1.3821	PctDefSpec	0
StdDev	1.665E06	Cpl	1.3375	NWithinSpec	78
W	0.8779	Cpu	1.4267	NOutsideSpec	0
WpValue	0.0000	Cpk	1.3375		
90%	16.216E06	Skew	0.6704		
75%	15.000E06	Kurtosis	-0.5996		
Median	13.043E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

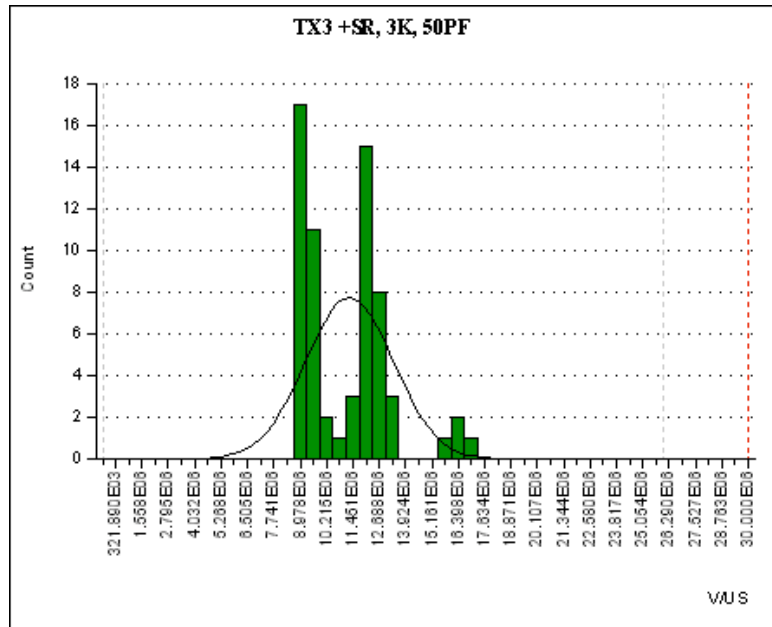
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=11.002, Test.Name=TX3 +SR, 3K, 50PF



Statistics: (V/US)

Max	17.143E06	25%	9.231E06	SpecHigh	30.000E06
Mean	11.147E06	10%	9.091E06	SpecLow	N/A
Min	8.824E06	N	64	PctWithinSpec	100.00
Range	8.319E06	Cp	N/A	c	
StdDev	2.036E06	Cpl	N/A	PctDefSpec	0
W	0.8615	Cpu	3.0859	NWithinSpec	64
WpValue	0.0000	Cpk	3.0859	NOutsideSpec	0
90%	13.043E06	Skew	0.9420		
75%	12.245E06	Kurtosis	0.7563		
Median	11.430E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

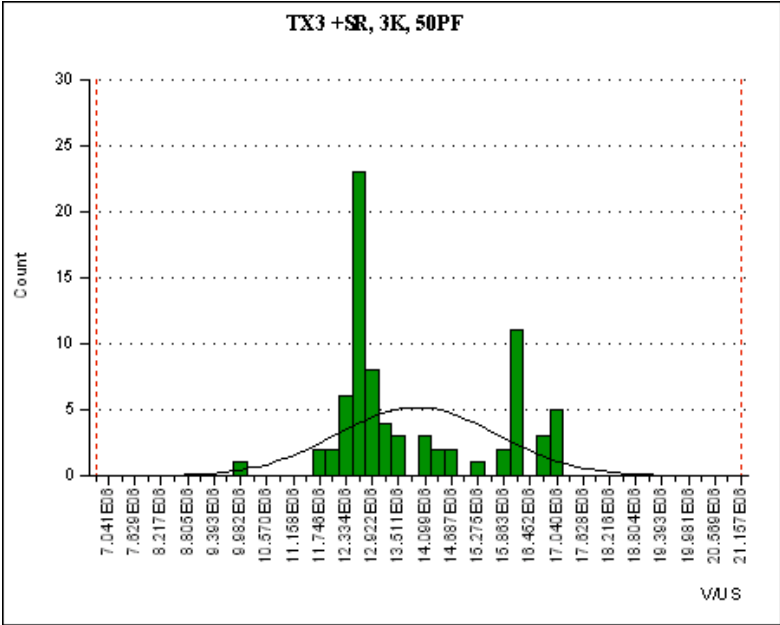
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
26.001E06	-296.404E03	100.00	0	64	0

Plot limits applied

NOutsidePlot

0

Test.Number=11.002, Test.Name=TX3 +SR, 3K, 50PF



Statistics: (V/US)

Max	17.143E06	25%	12.500E06	SpecHigh	21.157E06
Mean	13.854E06	10%	12.245E06	SpecLow	6.746E06
Min	9.836E06	N	78	PctWithinSpec	100.00
Range	7.307E06	Cp	1.3620	PctDefSpec	0
StdDev	1.763E06	Cpl	1.3435	NWithinSpec	78
W	0.8669	Cpu	1.3805	NOutsideSpec	0
WpValue	0.0000	Cpk	1.3435		
90%	16.667E06	Skew	0.5814		
75%	15.789E06	Kurtosis	-0.8384		
Median	13.043E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

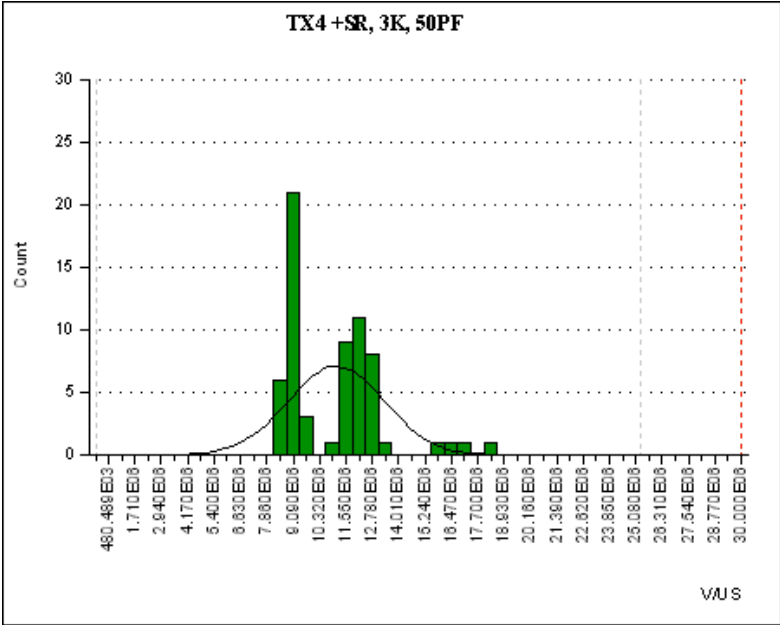
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=11.003, Test.Name=TX4 +SR, 3K, 50PF



Statistics: (V/US)

Max	18.182E06	25%	9.023E06	SpecHigh	30.000E06
Mean	10.970E06	10%	8.824E06	SpecLow	N/A
Min	8.333E06	N	64	PctWithinSpec	100.00
Range	9.848E06	Cp	N/A	PctDefSpec	0
StdDev	2.212E06	Cpl	N/A	NWithinSpec	64
W	0.8628	Cpu	2.8678	NOutsideSpec	0
WpValue	0.0000	Cpk	2.8678		
90%	13.043E06	Skew	1.0696		
75%	12.245E06	Kurtosis	1.3076		
Median	11.430E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

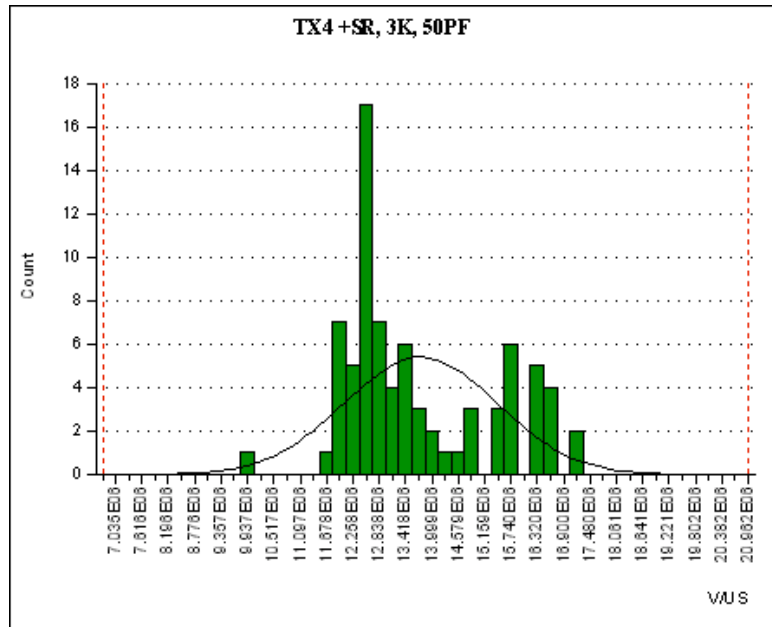
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
25.316E06	-134.501E03	100.00	0	64	0

Plot limits applied

NOutsidePlot
0

Test.Number=11.003, Test.Name=TX4 +SR, 3K, 50PF



Statistics: (V/US)

Max	17.143E06	25%	12.500E06	SpecHigh	20.962E06
Mean	13.673E06	10%	12.000E06	SpecLow	6.745E06
Min	9.836E06	N	78	PctWithinSpec	100.00
Range	7.307E06	Cp	1.4205	PctDefSpec	0
StdDev	1.668E06	Cpl	1.3844	NWithinSpec	78
W	0.8803	Cpu	1.4565	NOutsideSpec	0
WpValue	0.0000	Cpk	1.3844		
90%	16.216E06	Skew	0.5982		
75%	15.385E06	Kurtosis	-0.7274		
Median	13.043E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

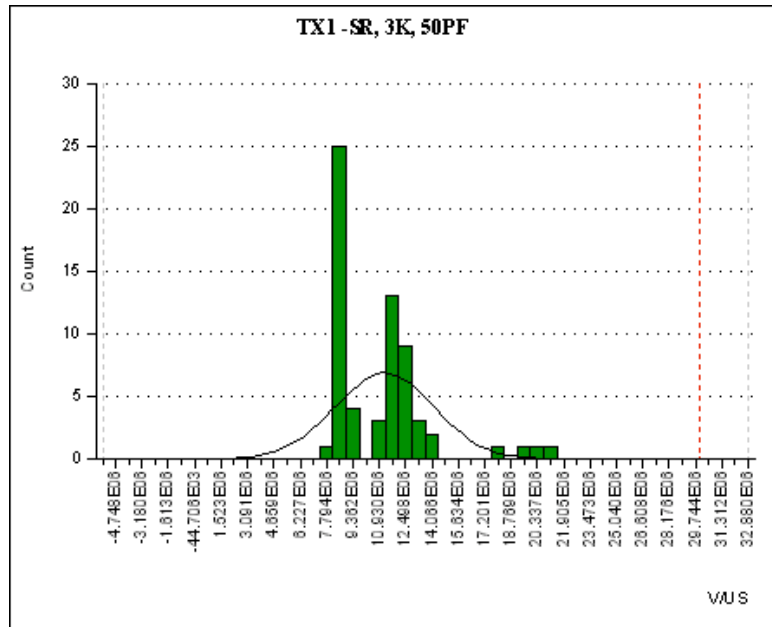
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=11.004, Test.Name=TX1 -SR, 3K, 50PF



Statistics: (V/US)

Max	21.429E06	25%	8.696E06	SpecHigh	30.000E06
Mean	11.066E06	10%	8.571E06	SpecLow	N/A
Min	8.000E06	N	64	PctWithinSpec	100.00
Range	13.429E06	Cp	N/A	PctDefSpec	0
StdDev	2.909E06	Cpl	N/A	NWithinSpec	64
W	0.8037	Cpu	2.1698	NOutsideSpec	0
WpValue	0.0000	Cpk	2.1698		
90%	13.636E06	Skew	1.5985		
75%	12.245E06	Kurtosis	3.1643		
Median	11.321E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

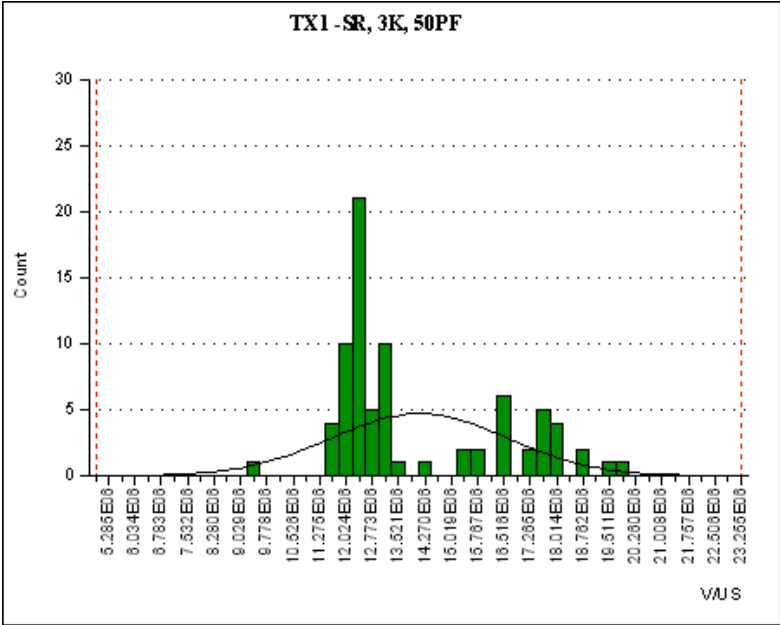
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
32.880E06	-5.532E06	100.00	0	64	0

Plot limits applied

NOutsidePlot

0

Test.Number=11.004, Test.Name=TX1 -SR, 3K, 50PF



Statistics: (V/US)

Max	20.000E06	25%	12.245E06	SpecHigh	23.255E06
Mean	14.028E06	10%	12.000E06	SpecLow	4.911E06
Min	9.375E06	N	78	PctWithinSpec	100.00
Range	10.625E06	Cp	1.2368	PctDefSpec	0
StdDev	2.472E06	Cpl	1.2293	NWithinSpec	78
W	0.8277	Cpu	1.2442	NOutsideSpec	0
WpValue	0.0000	Cpk	1.2293		
90%	18.182E06	Skew	0.8326		
75%	16.667E06	Kurtosis	-0.6592		
Median	12.766E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

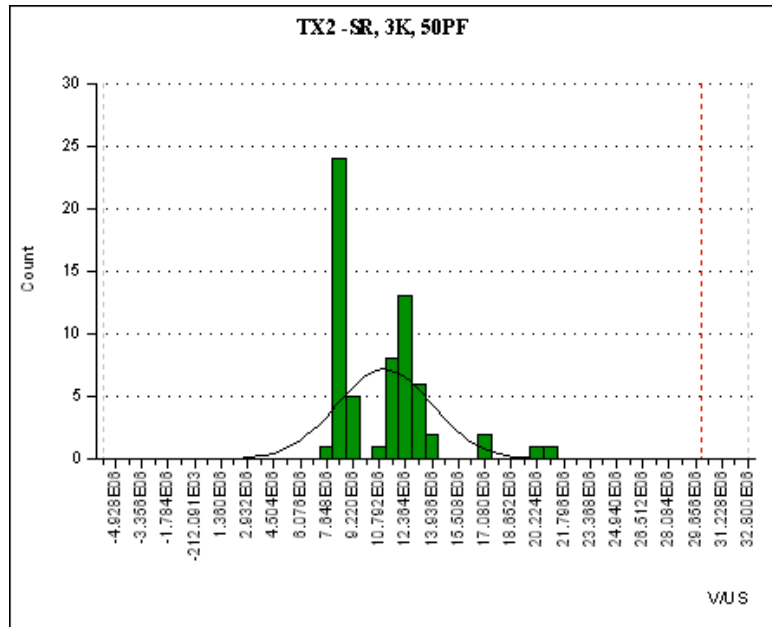
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=11.005, Test.Name=TX2 -SR, 3K, 50PF



Statistics: (V/US)

Max	20.690E06	25%	8.571E06	SpecHigh	30.000E06
Mean	10.929E06	10%	8.219E06	SpecLow	N/A
Min	7.895E06	N	64	PctWithinSpec	100.00
Range	12.795E06	Cp	N/A	PctDefSpec	0
StdDev	2.803E06	Cpl	N/A	NWithinSpec	64
W	0.8282	Cpu	2.2676	NOutsideSpec	0
WpValue	0.0000	Cpk	2.2676		
90%	13.333E06	Skew	1.3854		
75%	12.245E06	Kurtosis	2.5552		
Median	11.321E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

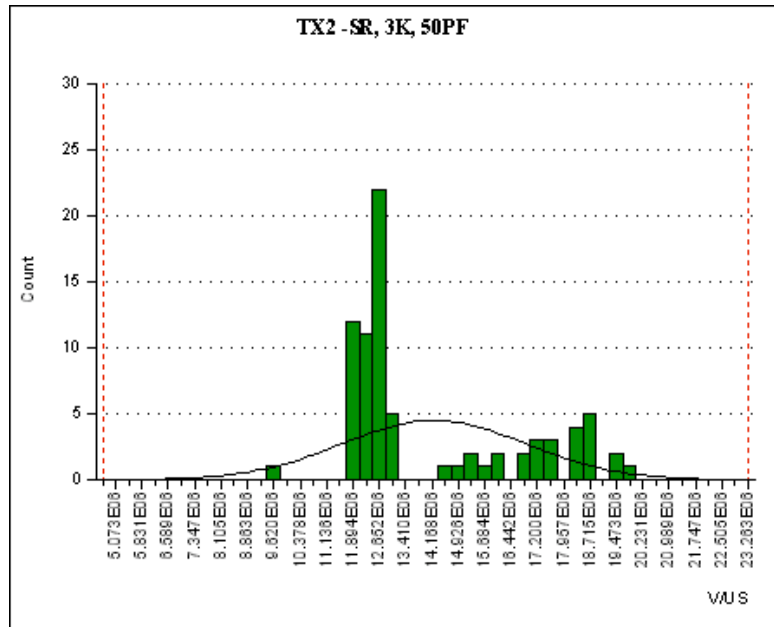
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
32.800E06	-5.714E06	100.00	0	64	0

Plot limits applied

NOutsidePlot

0

Test.Number=11.005, Test.Name=TX2 -SR, 3K, 50PF



Statistics: (V/US)

Max	20.000E06	25%	12.245E06	SpecHigh	23.263E06
Mean	14.134E06	10%	12.000E06	SpecLow	4.694E06
Min	9.524E06	N	78	PctWithinSpec	100.00
Range	10.476E06	Cp	1.1830	PctDefSpec	0
StdDev	2.616E06	Cpl	1.2028	NWithinSpec	78
W	0.8064	Cpu	1.1632	NOutsideSpec	0
WpValue	0.0000	Cpk	1.1632		
90%	18.750E06	Skew	0.8450		
75%	16.667E06	Kurtosis	-0.7695		
Median	12.766E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

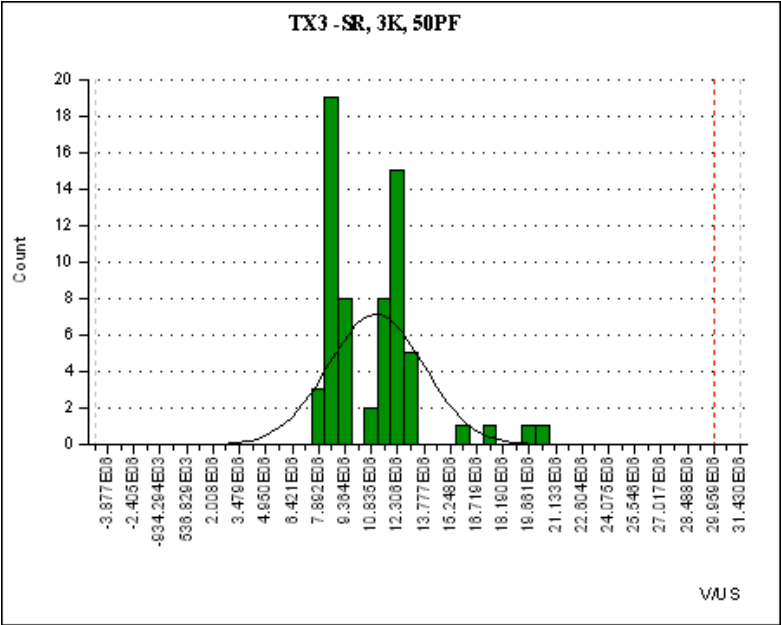
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=11.006, Test.Name=TX3 -SR, 3K, 50PF



Statistics: (V/US)

Max	20.690E06	25%	8.760E06	SpecHigh	30.000E06
Mean	10.918E06	10%	8.451E06	SpecLow	N/A
Min	7.692E06	N	64	PctWithinSpec	100.00
Range	12.997E06	Cp	N/A	c	
StdDev	2.625E06	Cpl	N/A	PctDefSpec	0
W	0.8338	Cpu	2.4232	NWithinSpec	64
WpValue	0.0000	Cpk	2.4232	NOutsideSpec	0
90%	13.043E06	Skew	1.4780		
75%	12.245E06	Kurtosis	3.2039		
Median	11.216E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

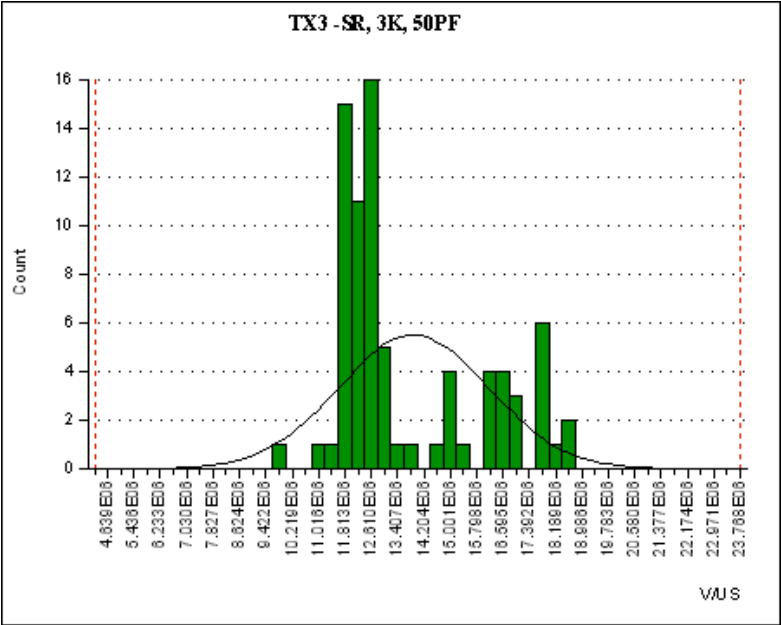
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
31.430E06	-4.612E06	100.00	0	64	0

Plot limits applied

NOutsidePlot
0

Test.Number=11.006, Test.Name=TX3 -SR, 3K, 50PF



Statistics: (V/US)

Max	18.750E06	25%	12.245E06	SpecHigh	23.768E06
Mean	13.785E06	10%	12.000E06	SpecLow	4.241E06
Min	9.677E06	N	78	PctWithinSpec	100.00
Range	9.073E06	Cp	1.4487	c	
StdDev	2.246E06	Cpl	1.4161	PctDefSpec	0
W	0.8333	Cpu	1.4813	NWithinSpec	78
WpValue	0.0000	Cpk	1.4161	NOutsideSpec	0
90%	17.647E06	Skew	0.8150		
75%	16.216E06	Kurtosis	-0.7138		
Median	12.633E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

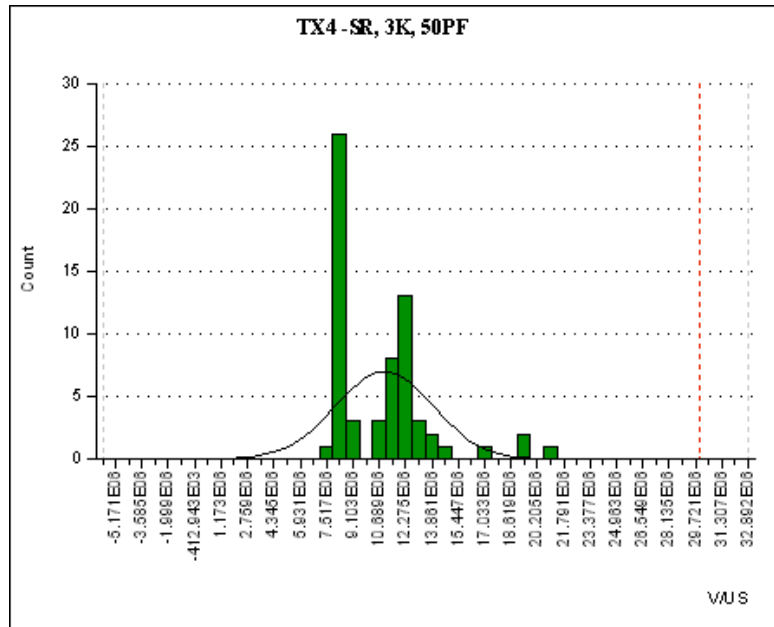
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=11.007, Test.Name=TX4 -SR, 3K, 50PF



Statistics: (V/US)

Max	20.690E06	25%	8.451E06	SpecHigh	30.000E06
Mean	10.811E06	10%	8.219E06	SpecLow	N/A
Min	7.792E06	N	64	PctWithinSpec	100.00
Range	12.897E06	Cp	N/A	PctDefSpec	0
StdDev	2.904E06	Cpl	N/A	NWithinSpec	64
W	0.8150	Cpu	2.2030	NOutsideSpec	0
WpValue	0.0000	Cpk	2.2030		
90%	13.954E06	Skew	1.4766		
75%	12.245E06	Kurtosis	2.5757		
Median	10.909E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

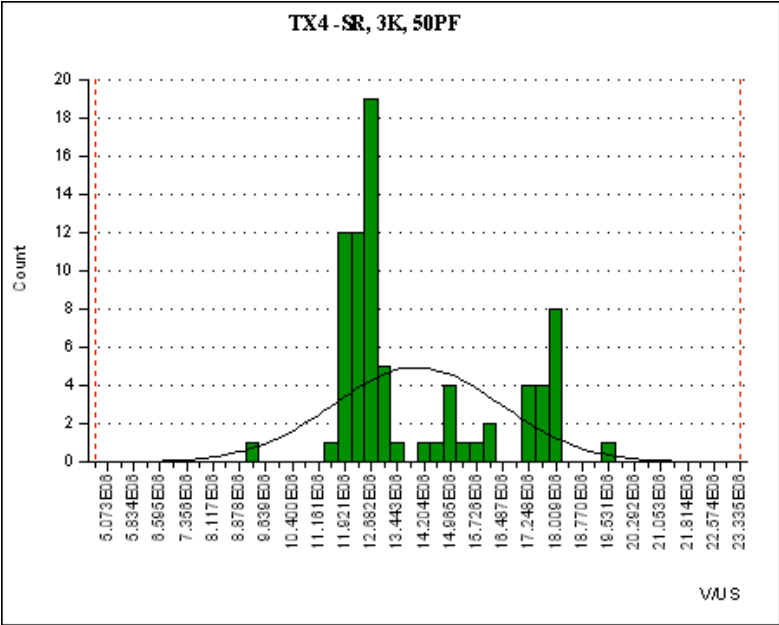
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
32.892E06	-5.964E06	100.00	0	64	0

Plot limits applied

NOutsidePlot

0

Test.Number=11.007, Test.Name=TX4 -SR, 3K, 50PF



Statistics: (V/US)

Max	19.355E06	25%	12.245E06	SpecHigh	23.335E06
Mean	13.911E06	10%	12.000E06	SpecLow	4.693E06
Min	9.231E06	N	78	PctWithinSpec	100.00
Range	10.124E06	Cp	1.3002	c	
StdDev	2.390E06	Cpl	1.2859	PctDefSpec	0
W	0.8077	Cpu	1.3145	NWithinSpec	78
WpValue	0.0000	Cpk	1.2859	NOutsideSpec	0
90%	18.182E06	Skew	0.8380		
75%	15.789E06	Kurtosis	-0.6774		
Median	12.500E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

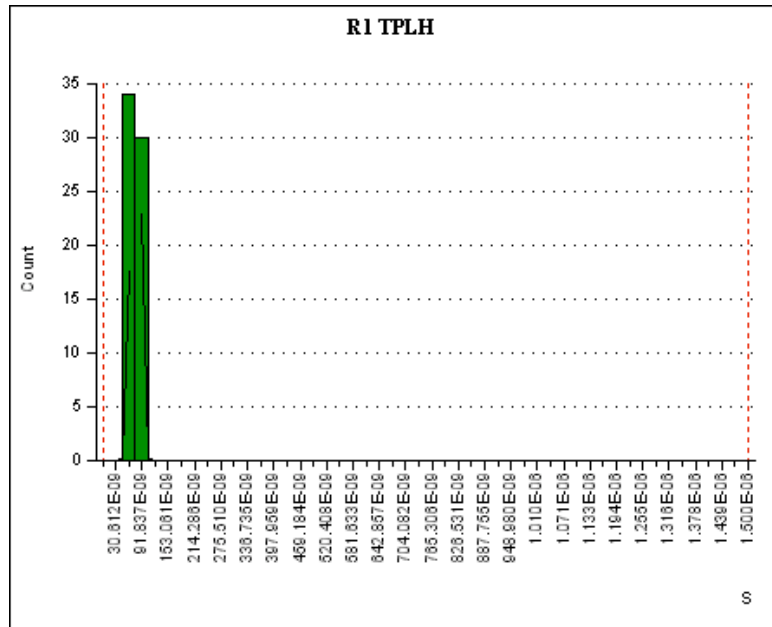
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=12.000, Test.Name=R1 TPLH



Statistics: (S)

Max	84.849E-09	25%	71.110E-09	SpecHigh	1.500E-06
Mean	75.658E-09	10%	70.552E-09	SpecLow	0
Min	50.646E-09	N	64	PctWithinSpec	100.00
Range	34.204E-09	Cp	>4.0000	c	
StdDev	8.647E-09	Cpl	2.9167	PctDefSpec	0
W	0.7630	Cpu	>4.0000	NWithinSpec	64
WpValue	0.0000	Cpk	2.9167	NOutsideSpec	0
90%	83.734E-09	Skew	-1.1827		
75%	83.269E-09	Kurtosis	1.5958		
Median	71.947E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

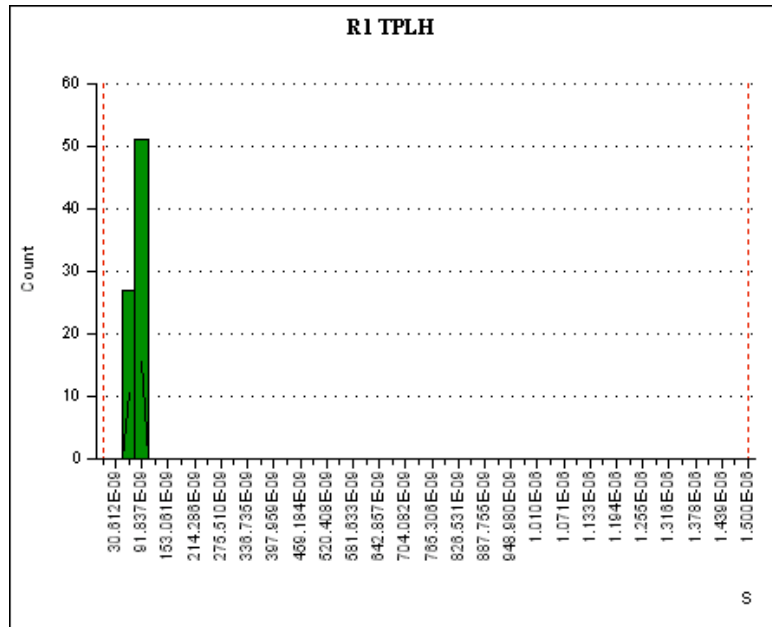
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.000, Test.Name=R1 TPLH



Statistics: (S)

Max	96.621E-09	25%	67.738E-09	SpecHigh	1.500E-06
Mean	75.607E-09	10%	65.378E-09	SpecLow	0
Min	63.585E-09	N	78	PctWithinSpec	100.00
Range	33.037E-09	Cp	>4.0000	c	
StdDev	6.878E-09	Cpl	3.6641	PctDefSpec	0
W	0.7715	Cpu	>4.0000	NWithinSpec	78
WpValue	0.0000	Cpk	3.6641	NOutsideSpec	0
90%	80.764E-09	Skew	-0.3365		
75%	80.103E-09	Kurtosis	-0.4003		
Median	79.584E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

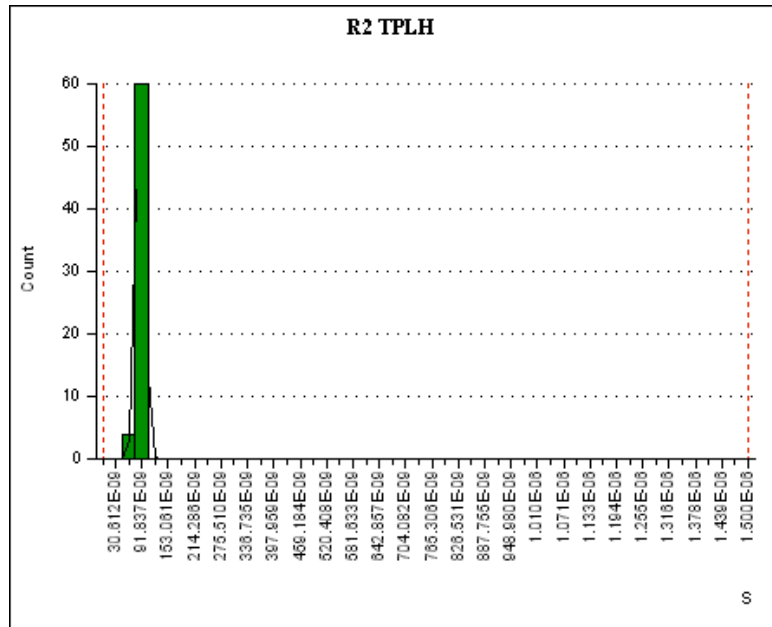
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.001, Test.Name=R2 TPLH



Statistics: (S)

Max	96.375E-09	25%	80.222E-09	SpecHigh	1.500E-06
Mean	85.925E-09	10%	79.385E-09	SpecLow	0
Min	57.802E-09	N	64	PctWithinSpec	100.00
Range	38.572E-09	Cp	>4.0000	PctDefSpec	0
StdDev	10.131E-09	Cpl	2.8270	NWithinSpec	64
W	0.7757	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	2.8270		
90%	95.538E-09	Skew	-1.0318		
75%	94.934E-09	Kurtosis	1.0785		
Median	81.430E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

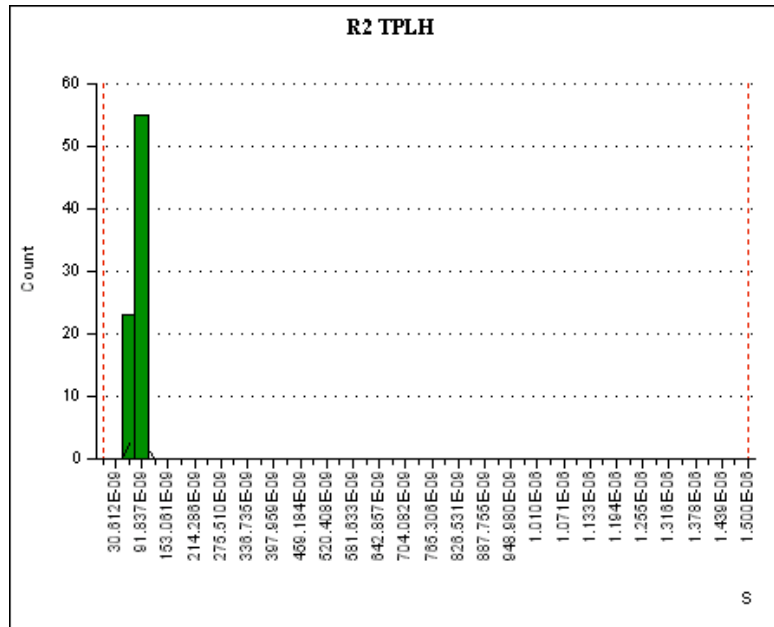
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.001, Test.Name=R2 TPLH



Statistics: (S)

Max	106.155E-09	25%	72.552E-09	SpecHigh	1.500E-06
Mean	81.775E-09	10%	70.286E-09	SpecLow	0
Min	68.493E-09	N	78	PctWithinSpec	100.00
Range	37.662E-09	Cp	>4.0000	PctDefSpec	0
StdDev	7.757E-09	Cpl	3.5142	NWithinSpec	78
W	0.7762	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	3.5142		
90%	87.465E-09	Skew	-0.2958		
75%	86.899E-09	Kurtosis	-0.2704		
Median	86.097E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

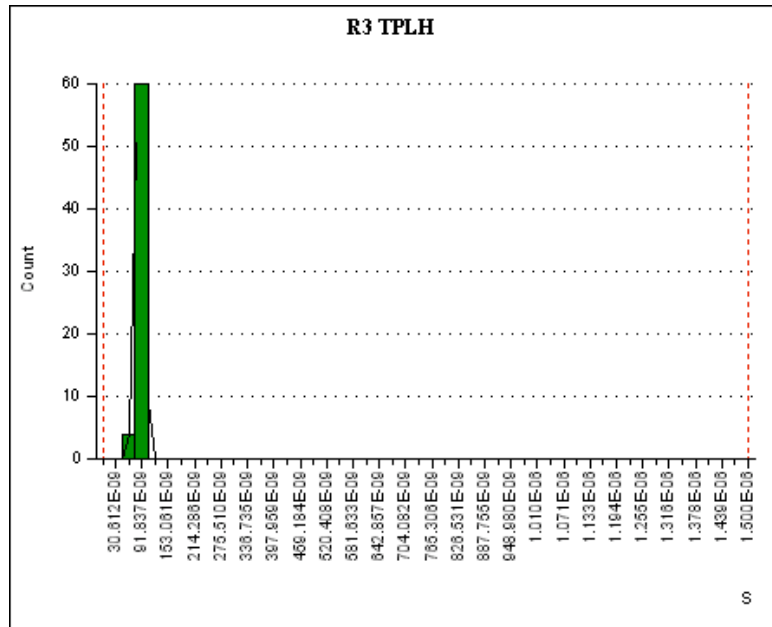
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.002, Test.Name=R3 TPLH



Statistics: (S)

Max	95.538E-09	25%	78.734E-09	SpecHigh	1.500E-06
Mean	84.349E-09	10%	78.083E-09	SpecLow	0
Min	57.059E-09	N	64	PctWithinSpec	100.00
Range	38.479E-09	Cp	>4.0000	PctDefSpec	0
StdDev	9.910E-09	Cpl	2.8371	NWithinSpec	64
W	0.7776	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	2.8371		
90%	93.772E-09	Skew	-0.9871		
75%	93.122E-09	Kurtosis	0.9385		
Median	79.850E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

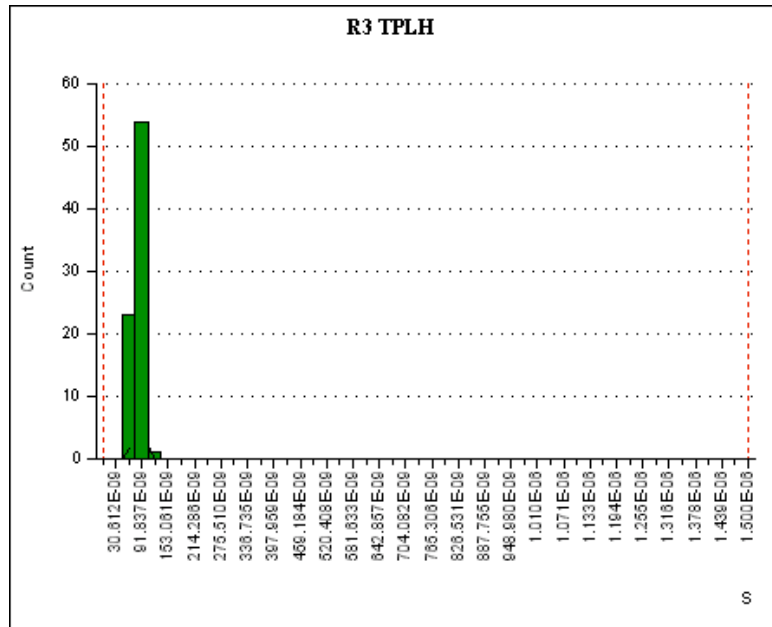
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.002, Test.Name=R3 TPLH



Statistics: (S)

Max	107.570E-09	25%	73.968E-09	SpecHigh	1.500E-06
Mean	82.702E-09	10%	71.230E-09	SpecLow	0
Min	69.626E-09	N	78	PctWithinSpec	100.00
Range	37.945E-09	Cp	>4.0000	PctDefSpec	0
StdDev	7.704E-09	Cpl	3.5782	NWithinSpec	78
W	0.7799	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	3.5782		
90%	88.504E-09	Skew	-0.2464		
75%	87.749E-09	Kurtosis	-0.1515		
Median	86.993E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

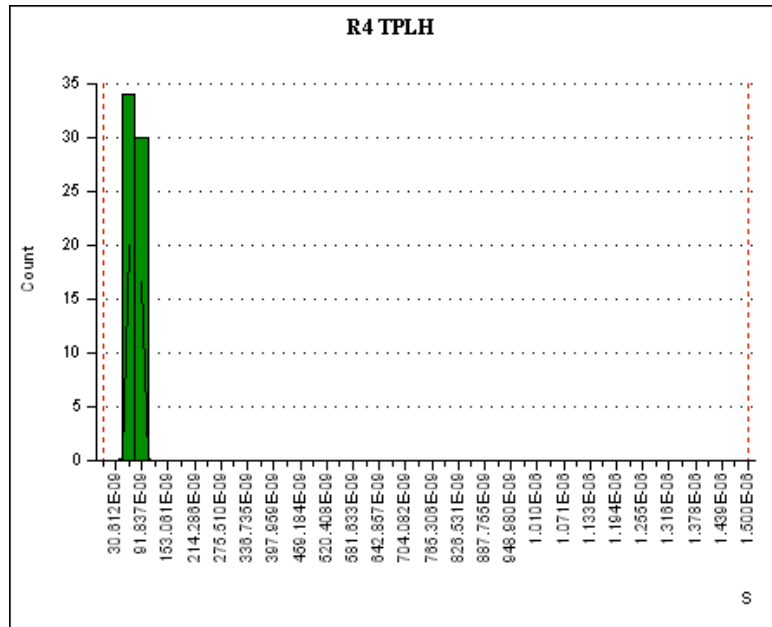
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.003, Test.Name=R4 TPLH



Statistics: (S)

Max	83.920E-09	25%	70.320E-09	SpecHigh	1.500E-06
Mean	74.571E-09	10%	69.529E-09	SpecLow	0
Min	50.553E-09	N	64	PctWithinSpec	100.00
Range	33.367E-09	Cp	>4.0000	c	
StdDev	8.275E-09	Cpl	3.0039	PctDefSpec	0
W	0.7761	Cpu	>4.0000	NWithinSpec	64
WpValue	0.0000	Cpk	3.0039	NOutsideSpec	0
90%	82.247E-09	Skew	-1.2245		
75%	81.596E-09	Kurtosis	1.7494		
Median	71.528E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

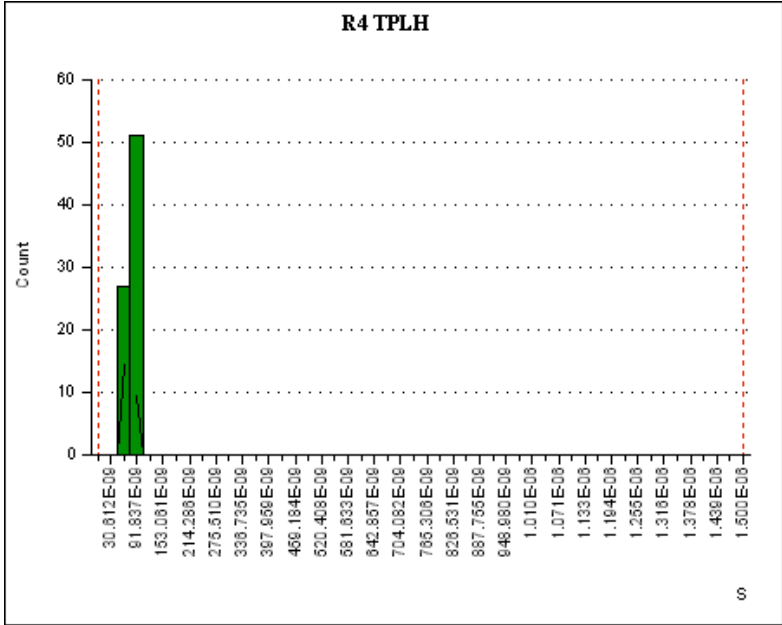
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.003, Test.Name=R4 TPLH



Statistics: (S)

Max	94.073E-09	25%	66.699E-09	SpecHigh	1.500E-06
Mean	74.352E-09	10%	64.151E-09	SpecLow	0
Min	62.735E-09	N	78	PctWithinSpec	100.00
Range	31.337E-09	Cp	>4.0000	c	
StdDev	6.705E-09	Cpl	3.6962	PctDefSpec	0
W	0.7737	Cpu	>4.0000	NWithinSpec	78
WpValue	0.0000	Cpk	3.6962	NOutsideSpec	0
90%	79.348E-09	Skew	-0.3868		
75%	78.781E-09	Kurtosis	-0.5394		
Median	78.121E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

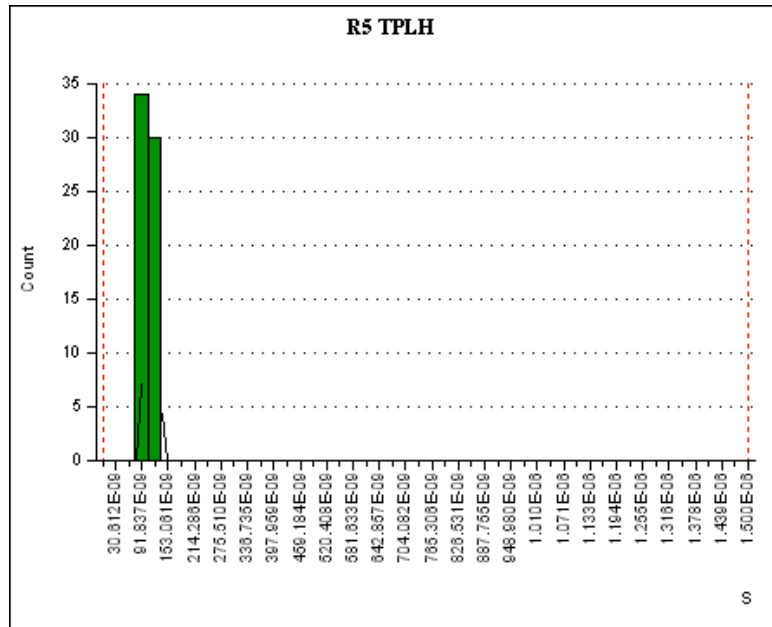
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=12.004, Test.Name=R5 TPLH



Statistics: (S)

Max	123.422E-09	25%	103.838E-09	SpecHigh	1.500E-06
Mean	111.500E-09	10%	102.788E-09	SpecLow	0
Min	82.526E-09	N	64	PctWithinSpec	100.00
Range	40.896E-09	Cp	>4.0000	c	
StdDev	9.750E-09	Cpl	3.8120	PctDefSpec	0
W	0.7939	Cpu	>4.0000	NWithinSpec	64
WpValue	0.0000	Cpk	3.8120	NOutsideSpec	0
90%	121.842E-09	Skew	-0.3571		
75%	121.145E-09	Kurtosis	-0.6305		
Median	106.069E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

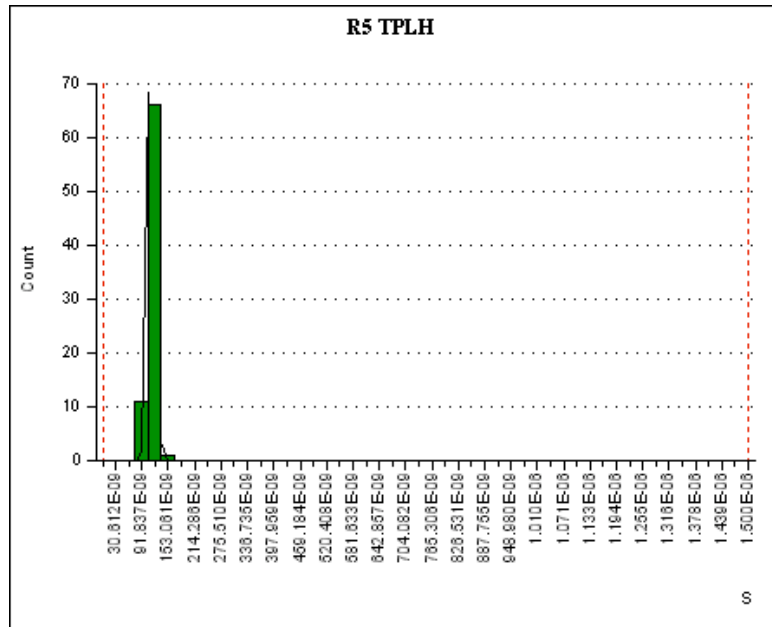
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.004, Test.Name=R5 TPLH



Statistics: (S)

Max	140.229E-09	25%	109.269E-09	SpecHigh	1.500E-06
Mean	113.418E-09	10%	106.910E-09	SpecLow	0
Min	103.700E-09	N	78	PctWithinSpec	100.00
Range	36.529E-09	Cp	>4.0000	c	
StdDev	7.885E-09	Cpl	>4.0000	PctDefSpec	0
W	0.7800	Cpu	>4.0000	NWithinSpec	78
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	129.186E-09	Skew	1.5900		
75%	113.328E-09	Kurtosis	1.7155		
Median	110.921E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T		0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T		0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T		0

Data: Raw Data

Stat limits applied

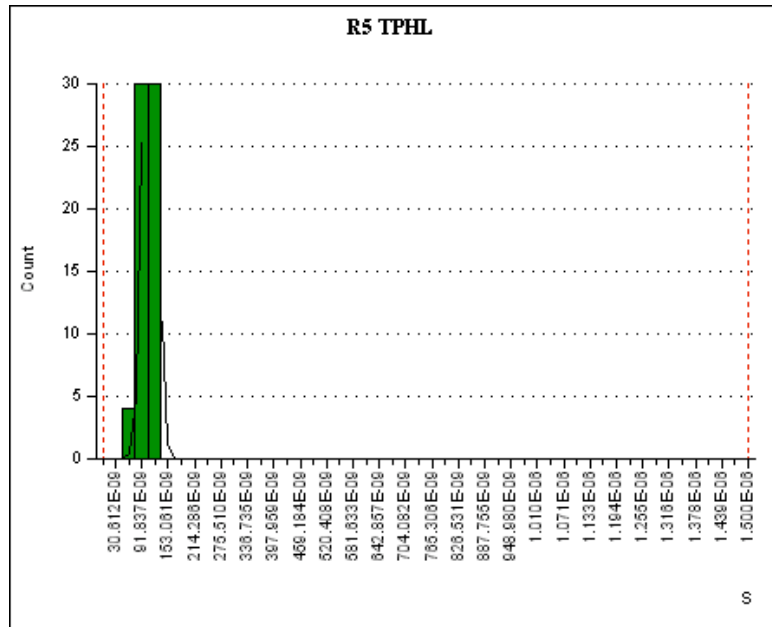
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.005, Test.Name=R5 TPHL



Statistics: (S)

Max	125.002E-09	25%	98.166E-09	SpecHigh	1.500E-06
Mean	108.141E-09	10%	97.608E-09	SpecLow	0
Min	69.978E-09	N	64	PctWithinSpec	100.00
Range	55.024E-09	Cp	>4.0000	PctDefSpec	0
StdDev	15.361E-09	Cpl	2.3467	NWithinSpec	64
W	0.7879	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	2.3467		
90%	123.701E-09	Skew	-0.5692		
75%	123.375E-09	Kurtosis	-0.3445		
Median	98.956E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

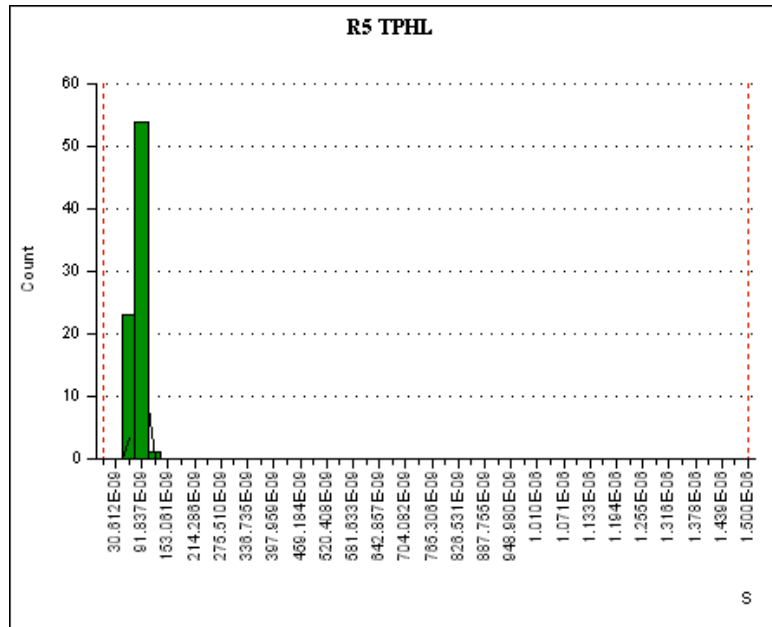
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.005, Test.Name=R5 TPHL



Statistics: (S)

Max	113.139E-09	25%	74.156E-09	SpecHigh	1.500E-06
Mean	84.262E-09	10%	70.381E-09	SpecLow	0
Min	68.115E-09	N	78	PctWithinSpec	100.00
Range	45.024E-09	Cp	>4.0000	c	
StdDev	9.213E-09	Cpl	3.0486	PctDefSpec	0
W	0.7615	Cpu	>4.0000	NWithinSpec	78
WpValue	0.0000	Cpk	3.0486	NOutsideSpec	0
90%	90.769E-09	Skew	-0.3141		
75%	90.391E-09	Kurtosis	-0.2632		
Median	89.684E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

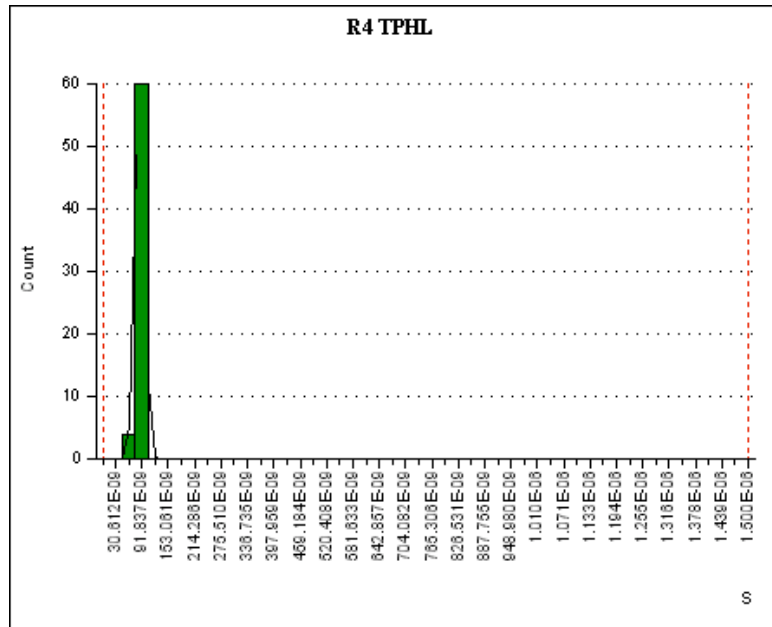
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.006, Test.Name=R4 TPHL



Statistics: (S)

Max	96.189E-09	25%	78.083E-09	SpecHigh	1.500E-06
Mean	84.616E-09	10%	77.432E-09	SpecLow	0
Min	56.780E-09	N	64	PctWithinSpec	100.00
Range	39.409E-09	Cp	>4.0000	PctDefSpec	0
StdDev	10.734E-09	Cpl	2.6276	NWithinSpec	64
W	0.7881	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	2.6276		
90%	95.538E-09	Skew	-0.7380		
75%	94.934E-09	Kurtosis	0.1654		
Median	78.781E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

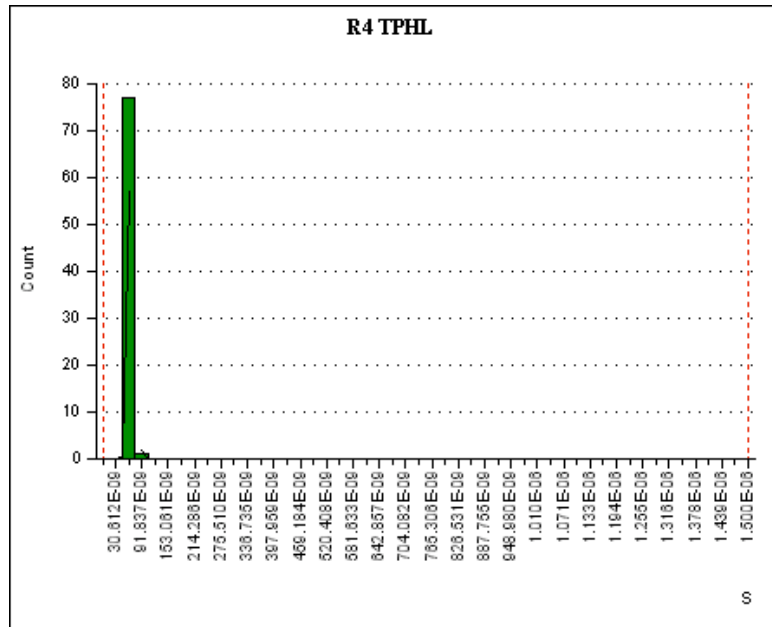
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.006, Test.Name=R4 TPHL



Statistics: (S)

Max	90.769E-09	25%	60.847E-09	SpecHigh	1.500E-06
Mean	69.253E-09	10%	58.865E-09	SpecLow	0
Min	57.166E-09	N	78	PctWithinSpec	100.00
Range	33.603E-09	Cp	>4.0000	PctDefSpec	0
StdDev	7.041E-09	Cpl	3.2784	NWithinSpec	78
W	0.7584	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	3.2784		
90%	74.345E-09	Skew	-0.3471		
75%	73.873E-09	Kurtosis	-0.3892		
Median	73.307E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

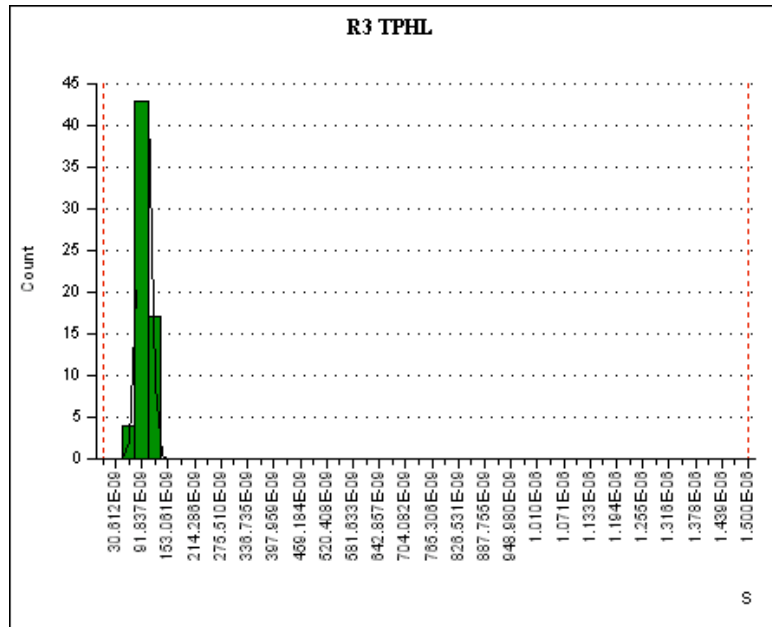
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.007, Test.Name=R3 TPHL



Statistics: (S)

Max	108.643E-09	25%	85.893E-09	SpecHigh	1.500E-06
Mean	94.324E-09	10%	85.428E-09	SpecLow	0
Min	60.963E-09	N	64	PctWithinSpec	100.00
Range	47.681E-09	Cp	>4.0000	PctDefSpec	0
StdDev	13.204E-09	Cpl	2.3813	NWithinSpec	64
W	0.7851	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	2.3813		
90%	107.714E-09	Skew	-0.6152		
75%	107.203E-09	Kurtosis	-0.2110		
Median	86.683E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

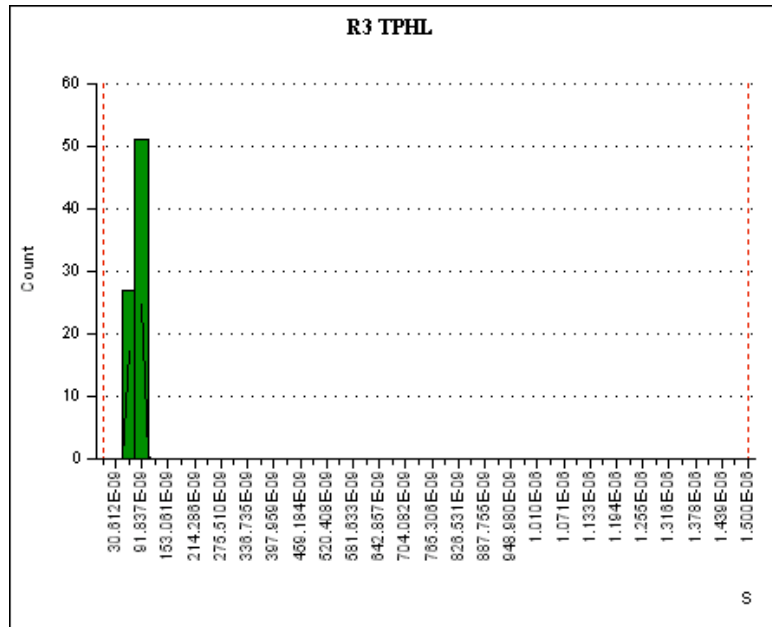
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.007, Test.Name=R3 TPHL



Statistics: (S)

Max	101.624E-09	25%	66.511E-09	SpecHigh	1.500E-06
Mean	75.777E-09	10%	64.057E-09	SpecLow	0
Min	61.980E-09	N	78	PctWithinSpec	100.00
Range	39.644E-09	Cp	>4.0000	PctDefSpec	0
StdDev	8.037E-09	Cpl	3.1427	NWithinSpec	78
W	0.7643	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	3.1427		
90%	81.519E-09	Skew	-0.2594		
75%	81.141E-09	Kurtosis	-0.1726		
Median	80.339E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

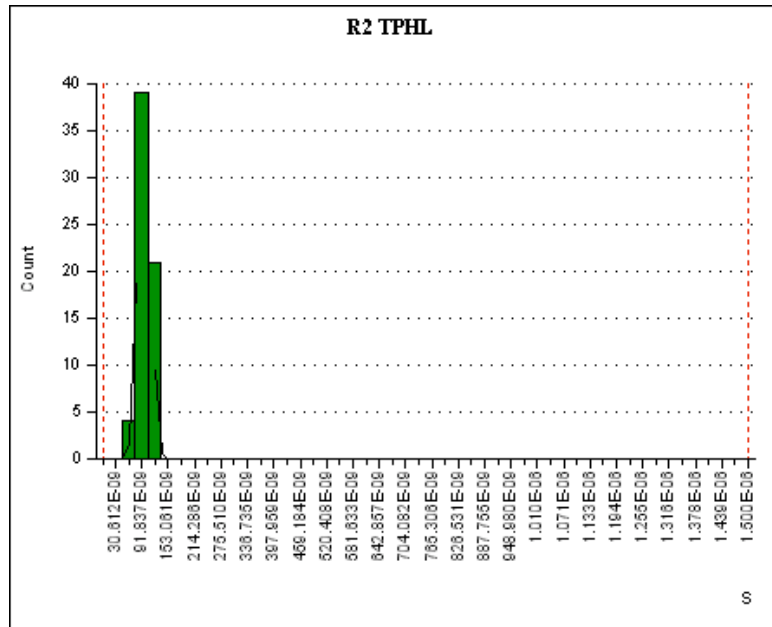
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.008, Test.Name=R2 TPHL



Statistics: (S)

Max	108.922E-09	25%	86.544E-09	SpecHigh	1.500E-06
Mean	94.906E-09	10%	86.172E-09	SpecLow	0
Min	62.078E-09	N	64	PctWithinSpec	100.00
Range	46.844E-09	Cp	>4.0000	PctDefSpec	0
StdDev	13.083E-09	Cpl	2.4180	NWithinSpec	64
W	0.7837	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	2.4180		
90%	108.272E-09	Skew	-0.6094		
75%	107.714E-09	Kurtosis	-0.2274		
Median	87.241E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

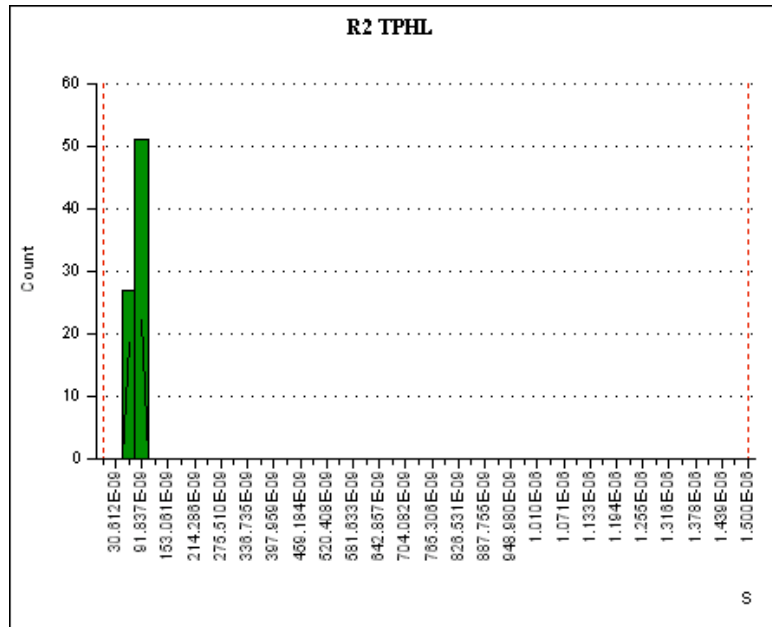
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.008, Test.Name=R2 TPHL



Statistics: (S)

Max	100.680E-09	25%	66.416E-09	SpecHigh	1.500E-06
Mean	75.400E-09	10%	63.585E-09	SpecLow	0
Min	61.697E-09	N	78	PctWithinSpec	100.00
Range	38.983E-09	Cp	>4.0000	PctDefSpec	0
StdDev	7.972E-09	Cpl	3.1525	NWithinSpec	78
W	0.7677	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	3.1525		
90%	81.141E-09	Skew	-0.2835		
75%	80.764E-09	Kurtosis	-0.2338		
Median	80.009E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

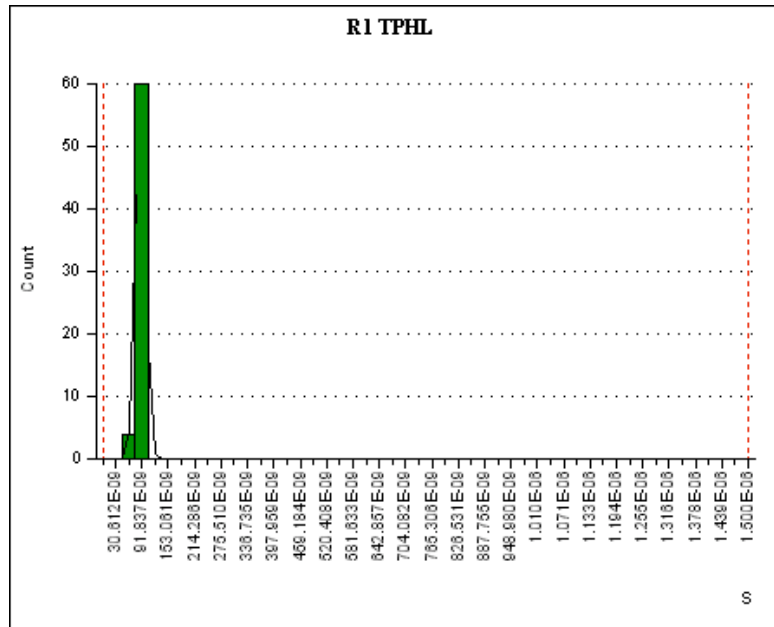
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.009, Test.Name=R1 TPHL



Statistics: (S)

Max	98.326E-09	25%	79.199E-09	SpecHigh	1.500E-06
Mean	86.225E-09	10%	78.920E-09	SpecLow	0
Min	56.687E-09	N	64	PctWithinSpec	100.00
Range	41.639E-09	Cp	>4.0000	PctDefSpec	0
StdDev	11.319E-09	Cpl	2.5393	NWithinSpec	64
W	0.7844	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	2.5393		
90%	97.583E-09	Skew	-0.7153		
75%	97.165E-09	Kurtosis	0.0930		
Median	80.129E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

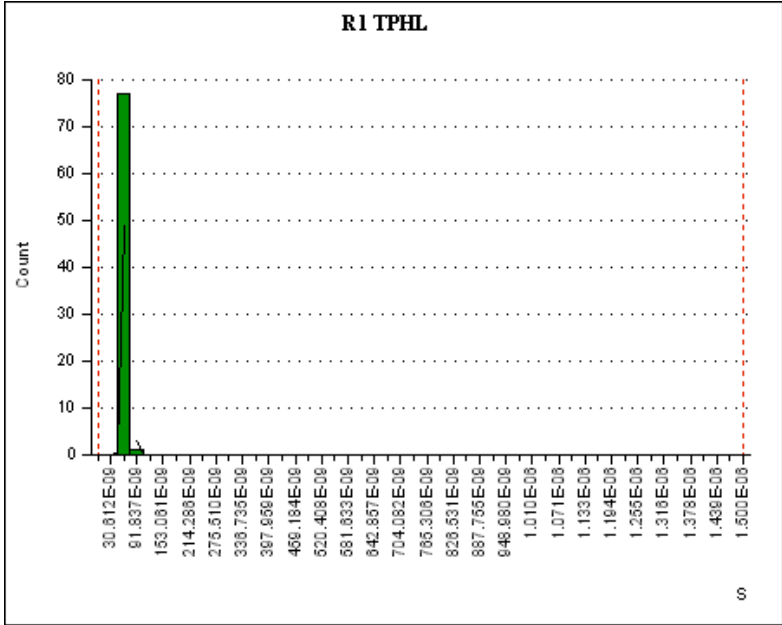
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.009, Test.Name=R1 TPHL



Statistics: (S)

Max	92.468E-09	25%	61.980E-09	SpecHigh	1.500E-06
Mean	70.158E-09	10%	59.715E-09	SpecLow	0
Min	57.449E-09	N	78	PctWithinSpec	100.00
Range	35.019E-09	Cp	>4.0000	c	
StdDev	7.173E-09	Cpl	3.2602	PctDefSpec	0
W	0.7621	Cpu	>4.0000	NWithinSpec	78
WpValue	0.0000	Cpk	3.2602	NOutsideSpec	0
90%	75.195E-09	Skew	-0.3163		
75%	74.911E-09	Kurtosis	-0.3209		
Median	74.345E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

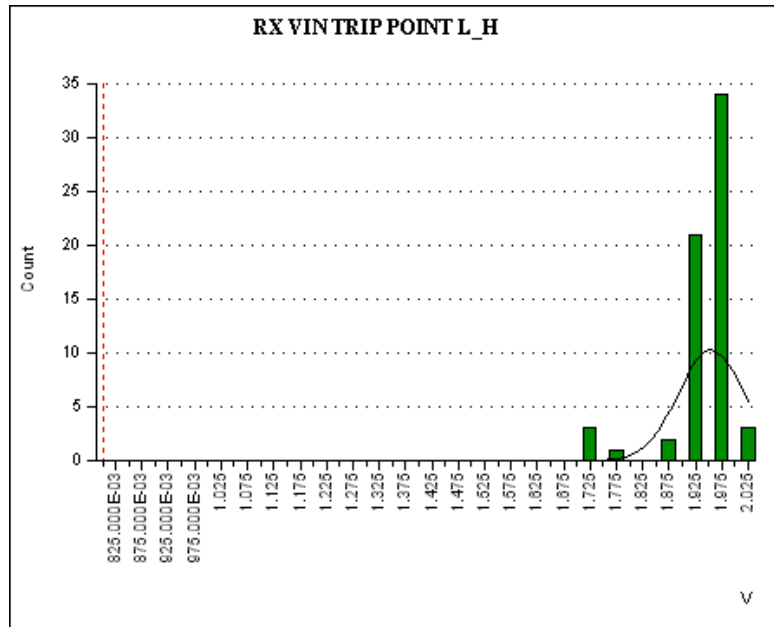
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=13.000, Test.Name=RX VIN TRIP POINT L_H



Statistics: (V)

Max	2.025	25%	1.925	SpecHigh	N/A
Mean	1.943	10%	1.925	SpecLow	800.000E-03
Min	1.725	N	64	PctWithinSpec	100.00
Range	300.000E-03	Cp	N/A	c	
StdDev	61.957E-03	Cpl	>4.0000	PctDefSpec	0
W	0.6654	Cpu	N/A	NWithinSpec	64
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	1.975	Skew	-2.3274		
75%	1.975	Kurtosis	6.0749		
Median	1.975				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

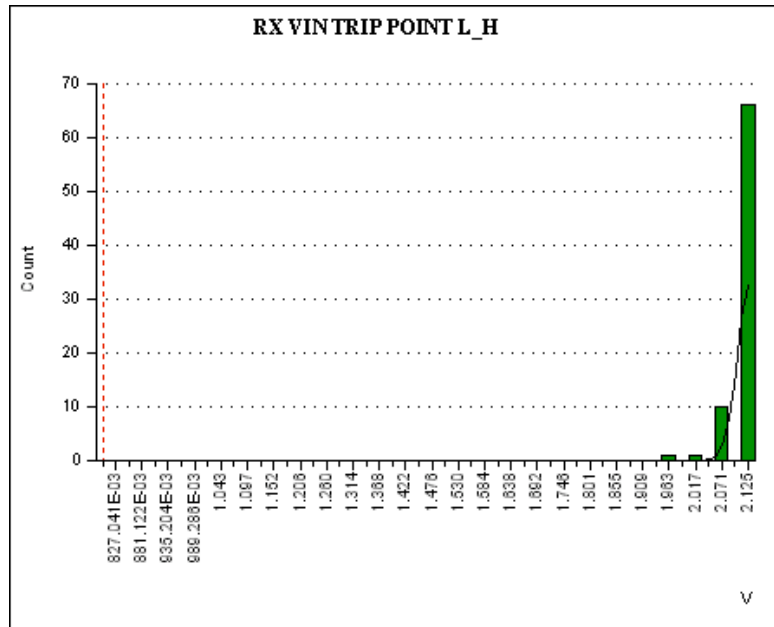
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.000, Test.Name=RX VIN TRIP POINT L_H



Statistics: (V)

Max	2.125	25%	2.125	SpecHigh	N/A
Mean	2.115	10%	2.075	SpecLow	800.000E-03
Min	1.975	N	78	PctWithinSpec	100.00
Range	150.000E-03	Cp	N/A	c	
StdDev	25.556E-03	Cpl	>4.0000	PctDefSpec	0
W	0.4260	Cpu	N/A	NWithinSpec	78
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	2.125	Skew	-3.2783		
75%	2.125	Kurtosis	12.7550		
Median	2.125				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

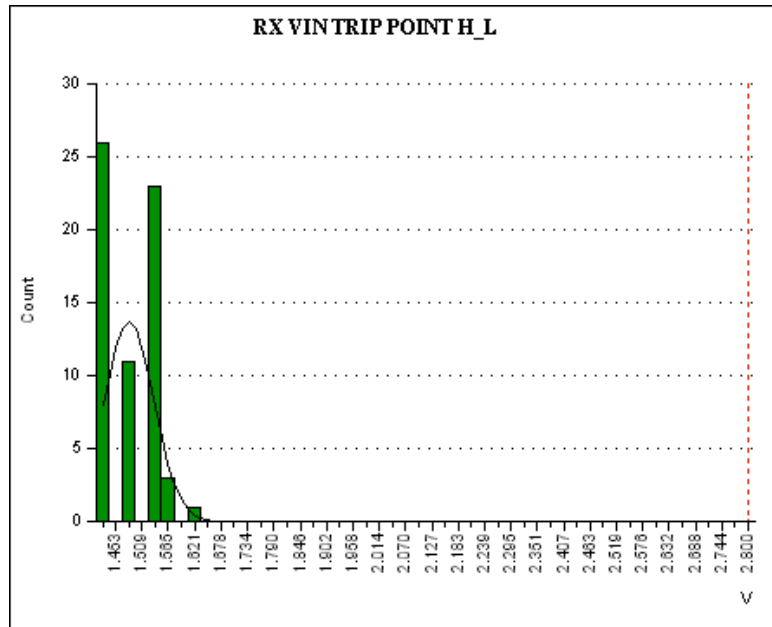
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.001, Test.Name=RX VIN TRIP POINT H_L



Statistics: (V)

Max	1.625	25%	1.425	SpecHigh	2.800
Mean	1.480	10%	1.425	SpecLow	N/A
Min	1.425	N	64	PctWithinSpec	100.00
Range	200.001E-03	Cp	N/A	PctDefSpec	0
StdDev	52.493E-03	Cpl	N/A	NWithinSpec	64
W	0.8191	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	1.525	Skew	0.4024		
75%	1.525	Kurtosis	-0.7959		
Median	1.475				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

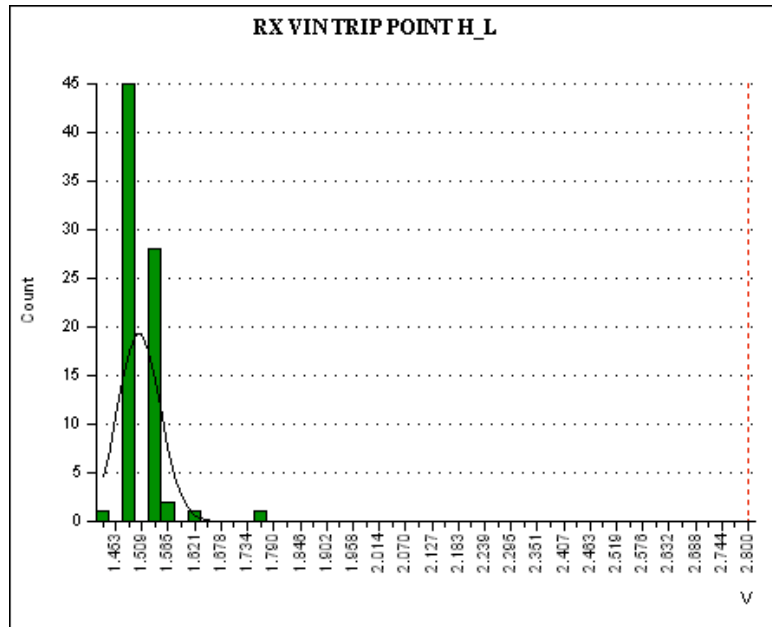
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=13.001, Test.Name=RX VIN TRIP POINT H_L



Statistics: (V)

Max	1.775	25%	1.475	SpecHigh	2.800
Mean	1.501	10%	1.475	SpecLow	N/A
Min	1.425	N	78	PctWithinSpec	100.00
Range	350.000E-03	Cp	N/A	PctDefSpec	0
StdDev	44.680E-03	Cpl	N/A	NWithinSpec	78
W	0.6044	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	1.525	Skew	3.3787		
75%	1.525	Kurtosis	18.1161		
Median	1.475				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

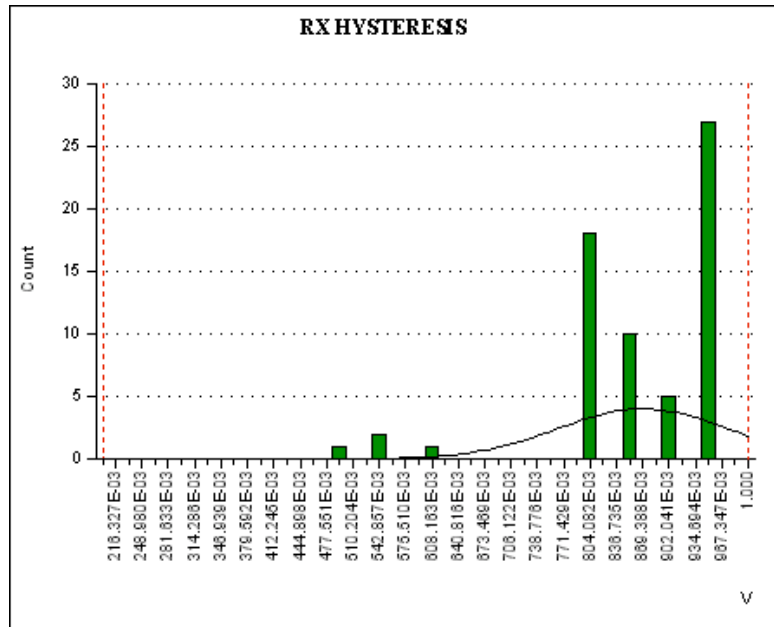
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.002, Test.Name=RX HYSTERESIS



Statistics: (V)

Max	950.001E-03	25%	800.001E-03	SpecHigh	1.000
Mean	863.282E-03	10%	800.001E-03	SpecLow	200.000E-03
Min	500.000E-03	N	64	PctWithinSpec	100.00
Range	450.001E-03	Cp	1.2822	PctDefSpec	0
StdDev	103.985E-03	Cpl	2.1262	NWithinSpec	64
W	0.7531	Cpu	0.4383	NOutsideSpec	0
WpValue	0.0000	Cpk	0.4383		
90%	950.001E-03	Skew	-1.6673		
75%	950.001E-03	Kurtosis	3.3194		
Median	875.001E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

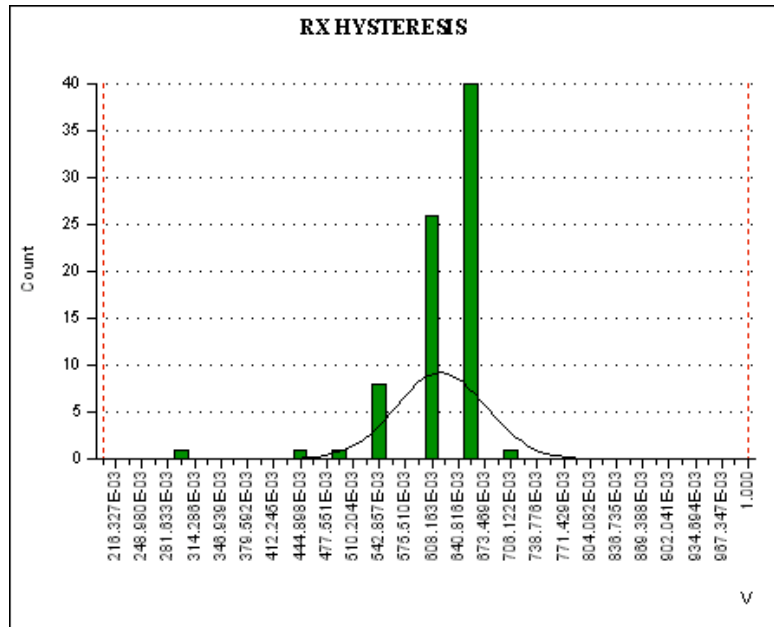
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.002, Test.Name=RX HYSTERESIS



Statistics: (V)

Max	700.001E-03	25%	600.000E-03	SpecHigh	1.000
Mean	614.744E-03	10%	550.001E-03	SpecLow	200.000E-03
Min	300.001E-03	N	78	PctWithinSpec	100.00
Range	400.000E-03	Cp	2.4107	PctDefSpec	0
StdDev	55.308E-03	Cpl	2.4996	NWithinSpec	78
W	0.6731	Cpu	2.3219	NOutsideSpec	0
WpValue	0.0000	Cpk	2.3219		
90%	650.001E-03	Skew	-2.9183		
75%	650.001E-03	Kurtosis	13.3531		
Median	650.001E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

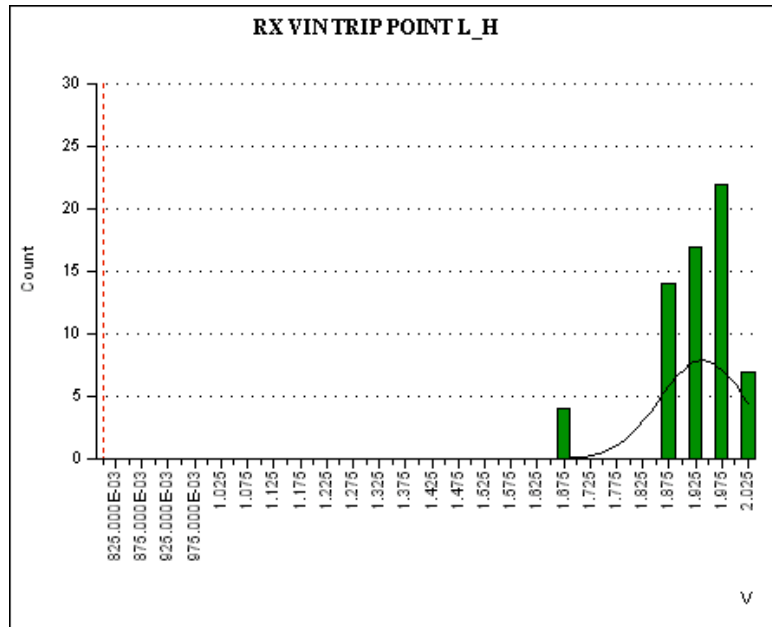
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.003, Test.Name=RX VIN TRIP POINT L_H



Statistics: (V)

Max	2.025	25%	1.875	SpecHigh	N/A
Mean	1.927	10%	1.875	SpecLow	800.000E-03
Min	1.675	N	64	PctWithinSpec	100.00
Range	350.000E-03	Cp	N/A	PctDefSpec	0
StdDev	80.657E-03	Cpl	>4.0000	NWithinSpec	64
W	0.7814	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	2.025	Skew	-1.7619		
75%	1.975	Kurtosis	3.8223		
Median	1.925				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

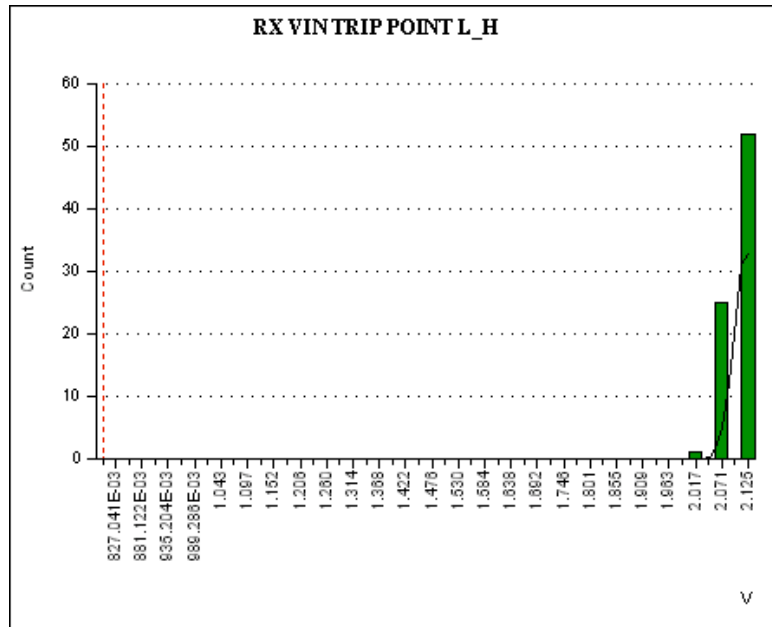
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.003, Test.Name=RX VIN TRIP POINT L_H



Statistics: (V)

Max	2.125	25%	2.075	SpecHigh	N/A
Mean	2.108	10%	2.075	SpecLow	800.000E-03
Min	2.025	N	78	PctWithinSpec	100.00
Range	99.999E-03	Cp	N/A	c	
StdDev	25.261E-03	Cpl	>4.0000	PctDefSpec	0
W	0.6268	Cpu	N/A	NWithinSpec	78
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	2.125	Skew	-0.9670		
75%	2.125	Kurtosis	-0.3627		
Median	2.125				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

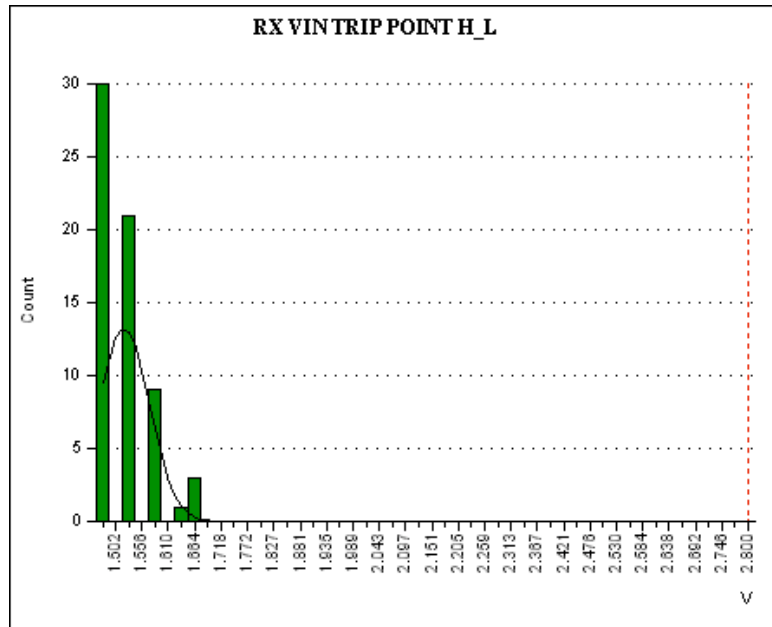
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.004, Test.Name=RX VIN TRIP POINT H_L



Statistics: (V)

Max	1.675	25%	1.475	SpecHigh	2.800
Mean	1.517	10%	1.475	SpecLow	N/A
Min	1.475	N	64	PctWithinSpec	100.00
Range	200.000E-03	Cp	N/A	PctDefSpec	0
StdDev	52.113E-03	Cpl	N/A	NWithinSpec	64
W	0.7614	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	1.575	Skew	1.4518		
75%	1.525	Kurtosis	2.0394		
Median	1.525				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

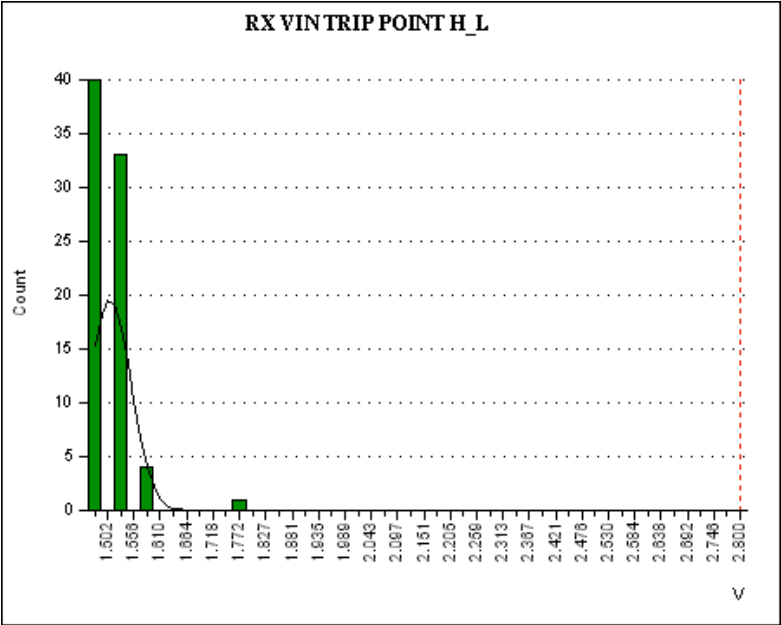
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.004, Test.Name=RX VIN TRIP POINT H_L



Statistics: (V)

Max	1.775	25%	1.475	SpecHigh	2.800
Mean	1.505	10%	1.475	SpecLow	N/A
Min	1.475	N	78	PctWithinSpec	100.00
Range	300.000E-03	Cp	N/A	PctDefSpec	0
StdDev	42.898E-03	Cpl	N/A	NWithinSpec	78
W	0.5992	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	1.525	Skew	3.4080		
75%	1.525	Kurtosis	19.4231		
Median	1.475				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

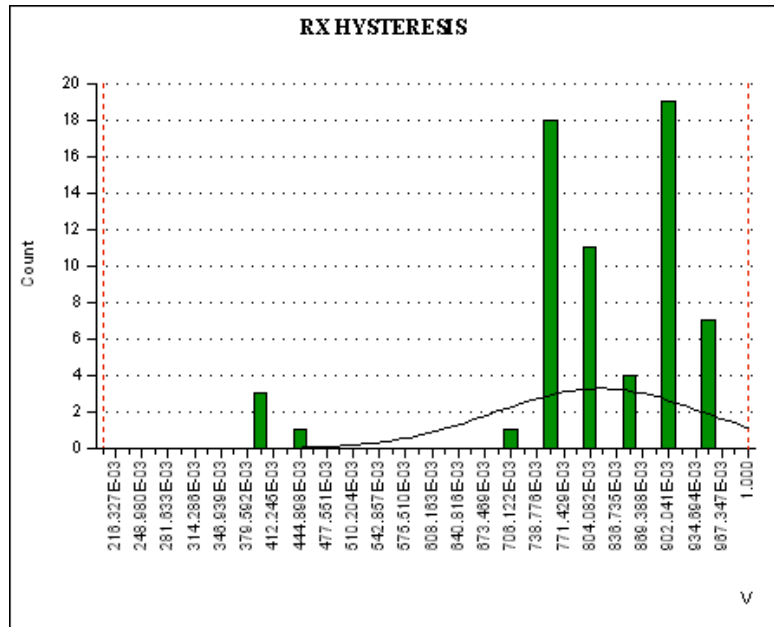
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=13.005, Test.Name=RX HYSTERESIS



Statistics: (V)

Max	950.001E-03	25%	750.000E-03	SpecHigh	1.000
Mean	809.376E-03	10%	750.000E-03	SpecLow	200.000E-03
Min	400.001E-03	N	64	PctWithinSpec	100.00
Range	550.000E-03	Cp	1.0534	PctDefSpec	0
StdDev	126.577E-03	Cpl	1.6047	NWithinSpec	64
W	0.7735	Cpu	0.5020	NOutsideSpec	0
WpValue	0.0000	Cpk	0.5020		
90%	950.001E-03	Skew	-1.8053		
75%	900.001E-03	Kurtosis	4.0159		
Median	800.001E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

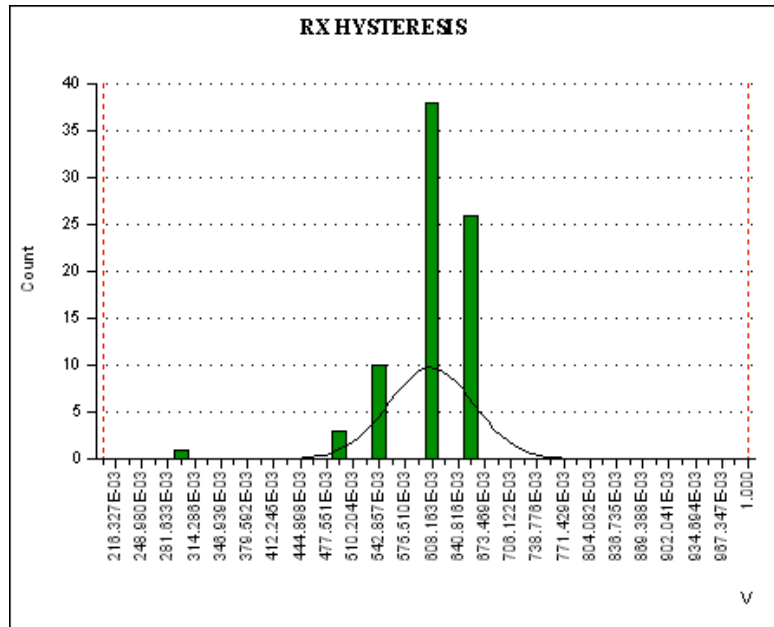
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.005, Test.Name=RX HYSTERESIS



Statistics: (V)

Max	650.001E-03	25%	600.000E-03	SpecHigh	1.000
Mean	602.565E-03	10%	550.001E-03	SpecLow	200.000E-03
Min	300.001E-03	N	78	PctWithinSpec	100.00
Range	349.999E-03	Cp	2.5563	PctDefSpec	0
StdDev	52.159E-03	Cpl	2.5727	NWithinSpec	78
W	0.6990	Cpu	2.5399	NOutsideSpec	0
WpValue	0.0000	Cpk	2.5399		
90%	650.001E-03	Skew	-2.7814		
75%	650.001E-03	Kurtosis	13.7999		
Median	600.001E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

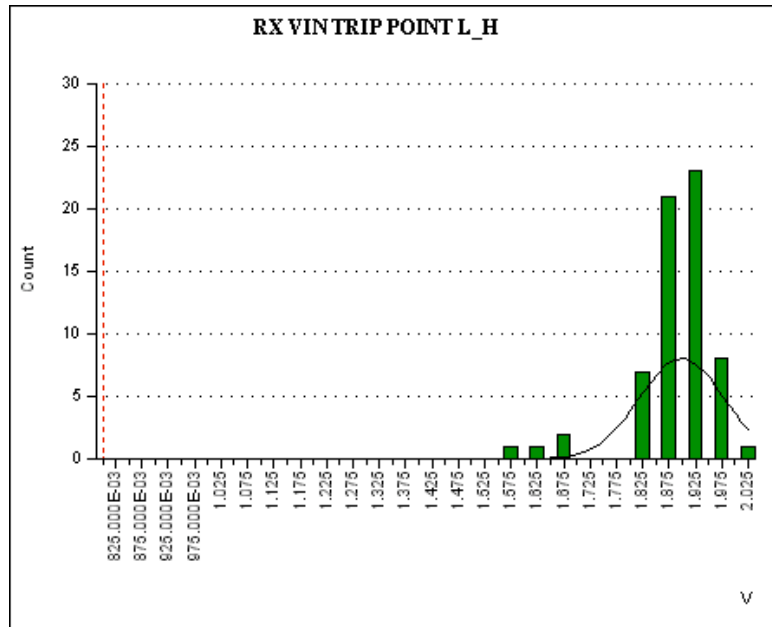
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.006, Test.Name=RX VIN TRIP POINT L_H



Statistics: (V)

Max	2.025	25%	1.875	SpecHigh	N/A
Mean	1.888	10%	1.825	SpecLow	800.000E-03
Min	1.575	N	64	PctWithinSpec	100.00
Range	450.000E-03	Cp	N/A	PctDefSpec	0
StdDev	79.682E-03	Cpl	>4.0000	NWithinSpec	64
W	0.7830	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	1.975	Skew	-1.9554		
75%	1.925	Kurtosis	5.2288		
Median	1.900				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

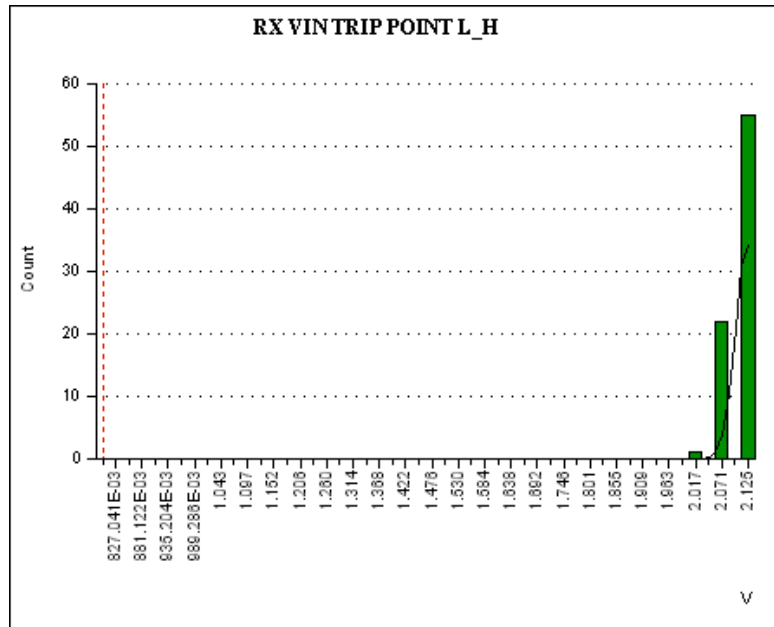
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.006, Test.Name=RX VIN TRIP POINT L_H



Statistics: (V)

Max	2.125	25%	2.075	SpecHigh	N/A
Mean	2.110	10%	2.075	SpecLow	800.000E-03
Min	2.025	N	78	PctWithinSpec	100.00
Range	99.999E-03	Cp	N/A	c	
StdDev	24.584E-03	Cpl	>4.0000	PctDefSpec	0
W	0.6012	Cpu	N/A	NWithinSpec	78
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	2.125	Skew	-1.1823		
75%	2.125	Kurtosis	0.1821		
Median	2.125				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

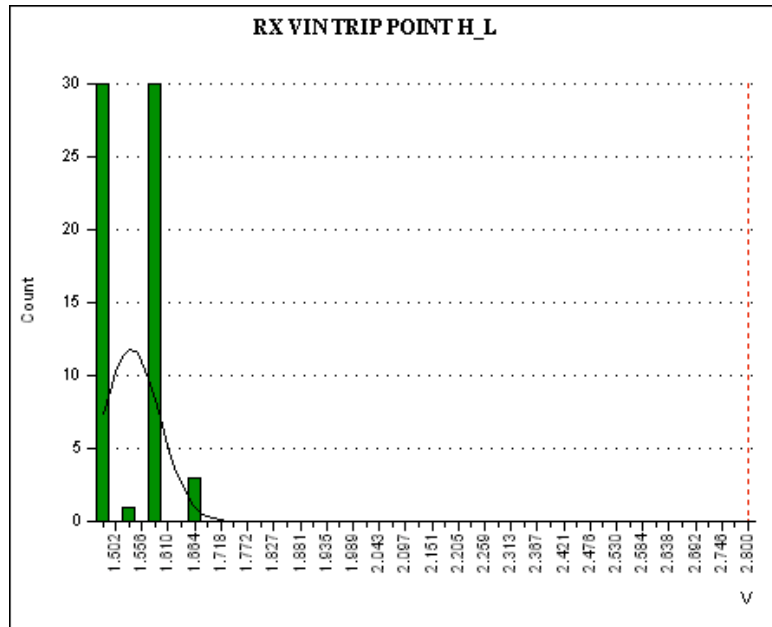
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.007, Test.Name=RX VIN TRIP POINT H_L



Statistics: (V)

Max	1.675	25%	1.475	SpecHigh	2.800
Mean	1.532	10%	1.475	SpecLow	N/A
Min	1.475	N	64	PctWithinSpec	100.00
Range	200.000E-03	Cp	N/A	PctDefSpec	0
StdDev	58.328E-03	Cpl	N/A	NWithinSpec	64
W	0.7367	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	1.575	Skew	0.4609		
75%	1.575	Kurtosis	-0.6247		
Median	1.575				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

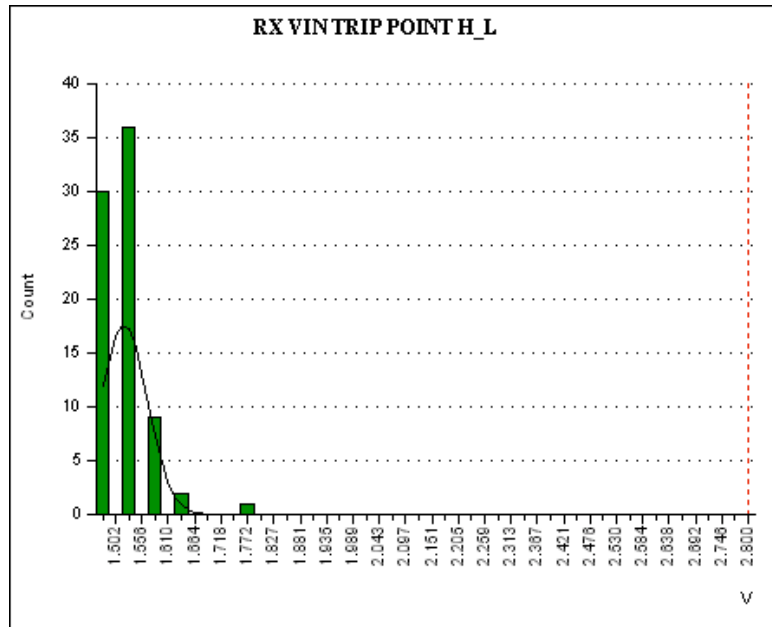
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=13.007, Test.Name=RX VIN TRIP POINT H_L



Statistics: (V)

Max	1.775	25%	1.475	SpecHigh	2.800
Mean	1.517	10%	1.475	SpecLow	N/A
Min	1.475	N	78	PctWithinSpec	100.00
Range	300.000E-03	Cp	N/A	PctDefSpec	0
StdDev	47.726E-03	Cpl	N/A	NWithinSpec	78
W	0.7202	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	1.575	Skew	2.3398		
75%	1.525	Kurtosis	10.0709		
Median	1.525				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

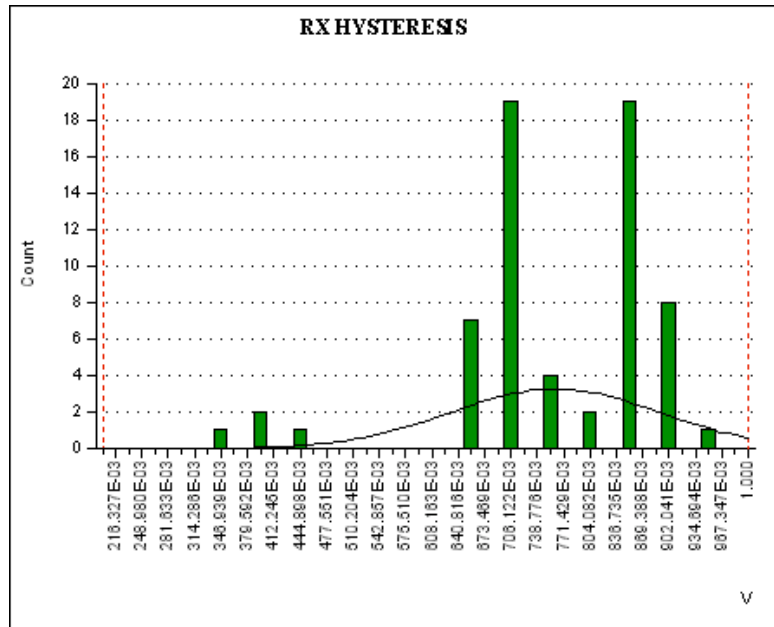
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.008, Test.Name=RX HYSTERESIS



Statistics: (V)

Max	950.001E-03	25%	700.000E-03	SpecHigh	1.000
Mean	755.469E-03	10%	650.001E-03	SpecLow	200.000E-03
Min	350.001E-03	N	64	PctWithinSpec	100.00
Range	600.000E-03	Cp	1.0450	PctDefSpec	0
StdDev	127.590E-03	Cpl	1.4512	NWithinSpec	64
W	0.8545	Cpu	0.6388	NOutsideSpec	0
WpValue	0.0000	Cpk	0.6388		
90%	900.001E-03	Skew	-1.1731		
75%	850.001E-03	Kurtosis	1.8035		
Median	750.000E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

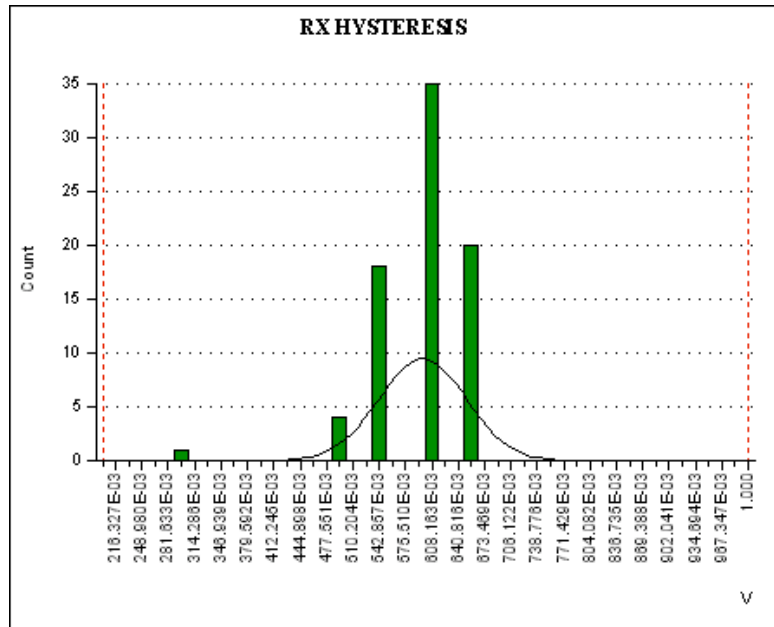
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N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.008, Test.Name=RX HYSTERESIS



Statistics: (V)

Max	650.001E-03	25%	550.001E-03	SpecHigh	1.000
Mean	592.308E-03	10%	550.000E-03	SpecLow	200.000E-03
Min	300.001E-03	N	78	PctWithinSpec	100.00
Range	349.999E-03	Cp	2.4923	PctDefSpec	0
StdDev	53.499E-03	Cpl	2.4443	NWithinSpec	78
W	0.7621	Cpu	2.5402	NOutsideSpec	0
WpValue	0.0000	Cpk	2.4443		
90%	650.001E-03	Skew	-2.2309		
75%	650.001E-03	Kurtosis	10.3682		
Median	600.000E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T		0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T		0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T		0

Data: Raw Data

Stat limits applied

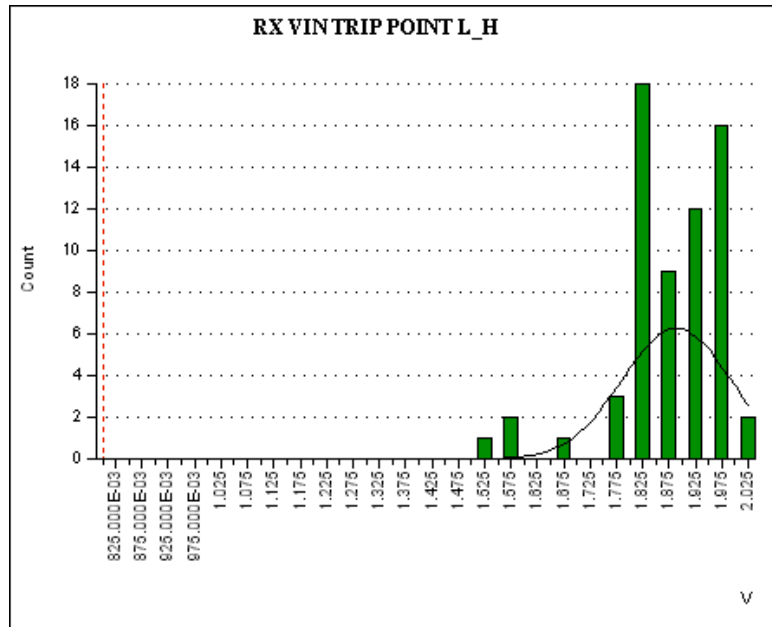
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.009, Test.Name=RX VIN TRIP POINT L_H



Statistics: (V)

Max	2.025	25%	1.825	SpecHigh	N/A
Mean	1.877	10%	1.775	SpecLow	800.000E-03
Min	1.525	N	64	PctWithinSpec	100.00
Range	500.000E-03	Cp	N/A	PctDefSpec	0
StdDev	101.743E-03	Cpl	3.5296	NWithinSpec	64
W	0.8504	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	3.5296		
90%	1.975	Skew	-1.4074		
75%	1.975	Kurtosis	2.8368		
Median	1.875				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

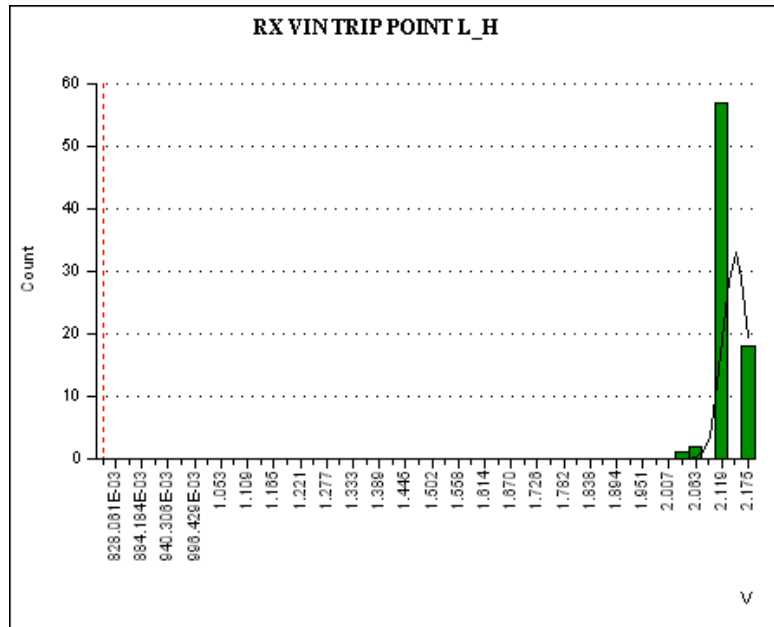
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.009, Test.Name=RX VIN TRIP POINT L_H



Statistics: (V)

Max	2.175	25%	2.125	SpecHigh	N/A
Mean	2.134	10%	2.125	SpecLow	800.000E-03
Min	2.025	N	78	PctWithinSpec	100.00
Range	150.000E-03	Cp	N/A	c	
StdDev	26.413E-03	Cpl	>4.0000	PctDefSpec	0
W	0.6466	Cpu	N/A	NWithinSpec	78
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	2.175	Skew	-0.3636		
75%	2.125	Kurtosis	3.1273		
Median	2.125				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

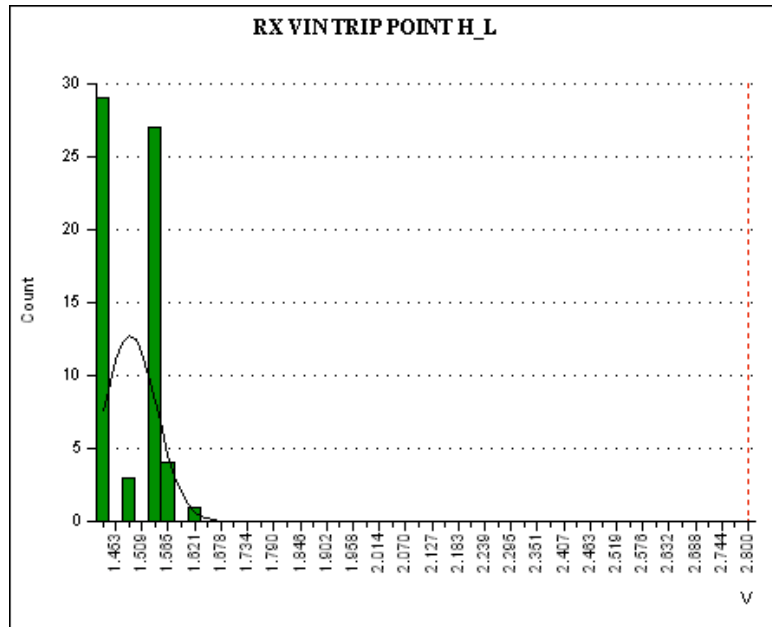
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.010, Test.Name=RX VIN TRIP POINT H_L



Statistics: (V)

Max	1.625	25%	1.425	SpecHigh	2.800
Mean	1.482	10%	1.425	SpecLow	N/A
Min	1.425	N	64	PctWithinSpec	100.00
Range	200.000E-03	Cp	N/A	PctDefSpec	0
StdDev	56.250E-03	Cpl	N/A	NWithinSpec	64
W	0.7734	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	1.525	Skew	0.2668		
75%	1.525	Kurtosis	-1.2030		
Median	1.500				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

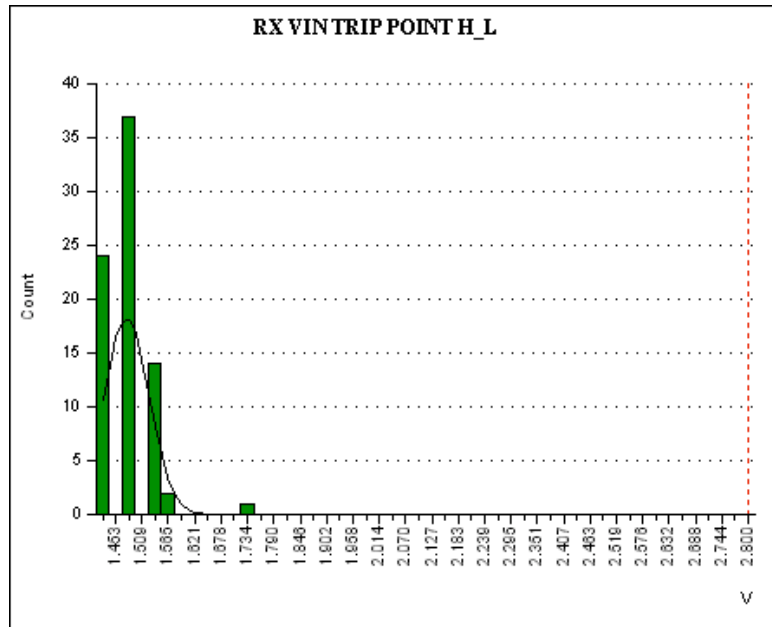
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.010, Test.Name=RX VIN TRIP POINT H_L



Statistics: (V)

Max	1.725	25%	1.425	SpecHigh	2.800
Mean	1.474	10%	1.425	SpecLow	N/A
Min	1.425	N	78	PctWithinSpec	100.00
Range	300.000E-03	Cp	N/A	PctDefSpec	0
StdDev	48.008E-03	Cpl	N/A	NWithinSpec	78
W	0.7600	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	1.525	Skew	2.0137		
75%	1.475	Kurtosis	8.4721		
Median	1.475				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

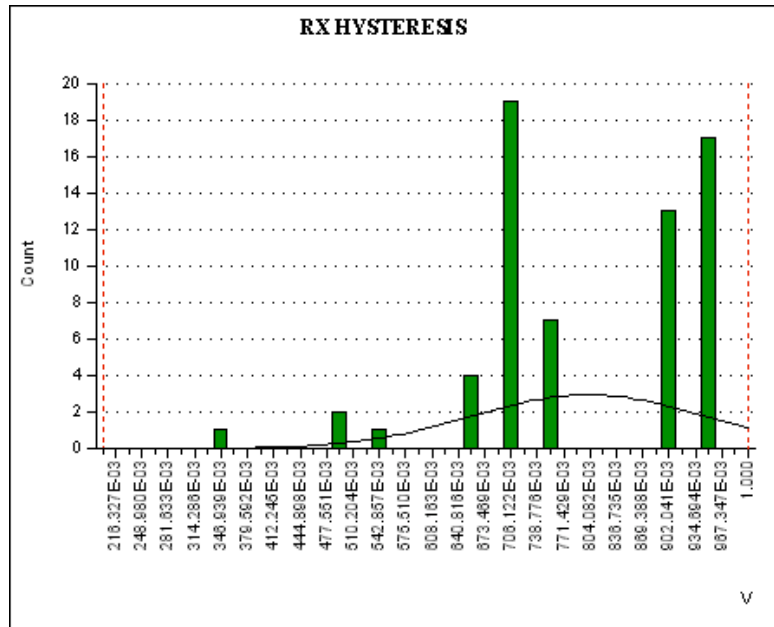
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.011, Test.Name=RX HYSTERESIS



Statistics: (V)

Max	950.001E-03	25%	700.001E-03	SpecHigh	1.000
Mean	795.314E-03	10%	650.001E-03	SpecLow	200.000E-03
Min	350.002E-03	N	64	PctWithinSpec	100.00
Range	599.999E-03	Cp	0.9452	PctDefSpec	0
StdDev	141.061E-03	Cpl	1.4067	NWithinSpec	64
W	0.8523	Cpu	0.4837	NOutsideSpec	0
WpValue	0.0000	Cpk	0.4837		
90%	950.001E-03	Skew	-0.6194		
75%	950.001E-03	Kurtosis	0.0633		
Median	750.001E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

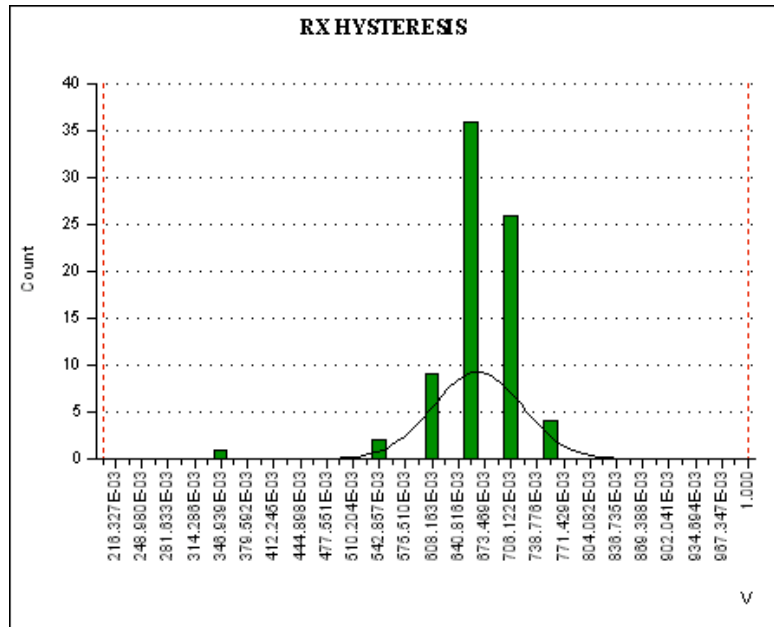
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.011, Test.Name=RX HYSTERESIS



Statistics: (V)

Max	750.001E-03	25%	650.002E-03	SpecHigh	1.000
Mean	659.617E-03	10%	600.001E-03	SpecLow	200.000E-03
Min	350.001E-03	N	78	PctWithinSpec	100.00
Range	400.000E-03	Cp	2.4381	PctDefSpec	0
StdDev	54.688E-03	Cpl	2.8015	NWithinSpec	78
W	0.7551	Cpu	2.0747	NOutsideSpec	0
WpValue	0.0000	Cpk	2.0747		
90%	700.002E-03	Skew	-2.4111		
75%	700.002E-03	Kurtosis	12.4631		
Median	650.002E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

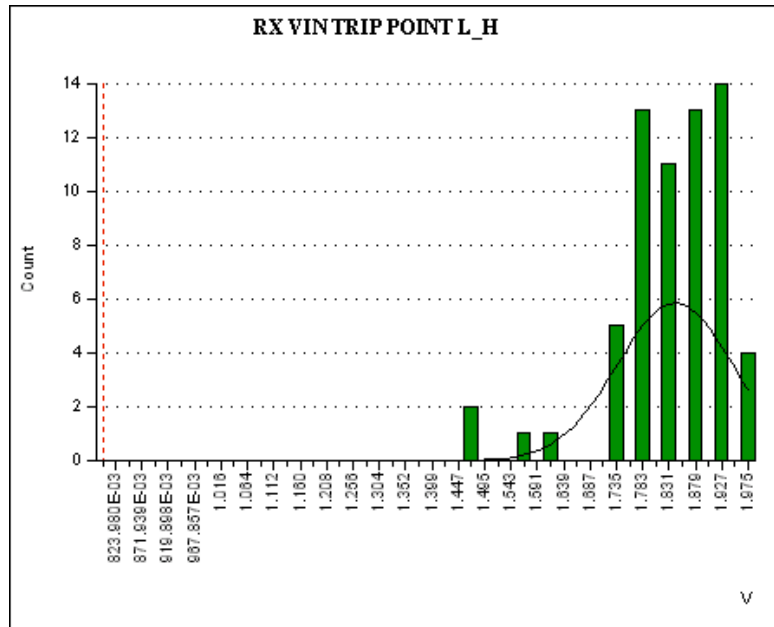
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.012, Test.Name=RX VIN TRIP POINT L_H



Statistics: (V)

Max	1.975	25%	1.775	SpecHigh	N/A
Mean	1.830	10%	1.725	SpecLow	800.000E-03
Min	1.475	N	64	PctWithinSpec	100.00
Range	500.000E-03	Cp	N/A	PctDefSpec	0
StdDev	104.698E-03	Cpl	3.2808	NWithinSpec	64
W	0.8708	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	3.2808		
90%	1.925	Skew	-1.4022		
75%	1.925	Kurtosis	2.9008		
Median	1.825				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

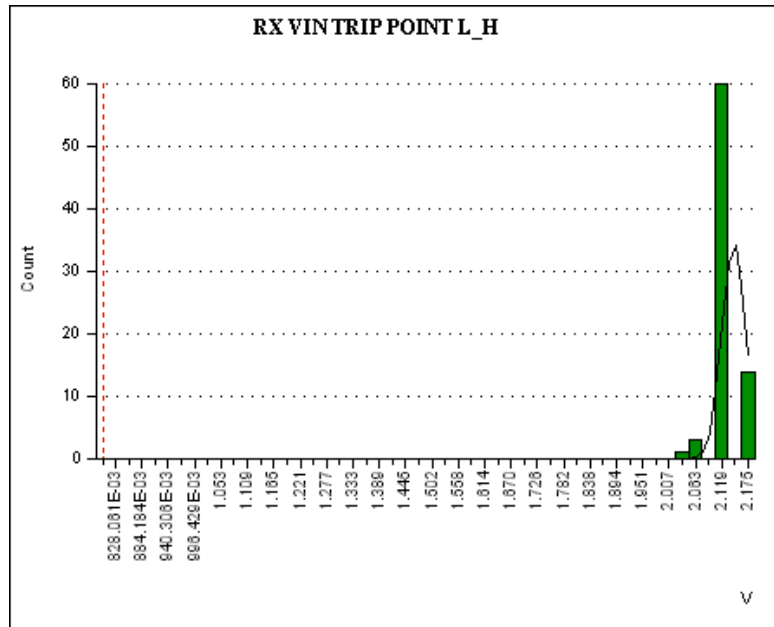
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.012, Test.Name=RX VIN TRIP POINT L_H



Statistics: (V)

Max	2.175	25%	2.125	SpecHigh	N/A
Mean	2.131	10%	2.125	SpecLow	800.000E-03
Min	2.025	N	78	PctWithinSpec	100.00
Range	150.000E-03	Cp	N/A	c	
StdDev	25.458E-03	Cpl	>4.0000	PctDefSpec	0
W	0.6296	Cpu	N/A	NWithinSpec	78
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	2.175	Skew	-0.4070		
75%	2.125	Kurtosis	3.8260		
Median	2.125				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

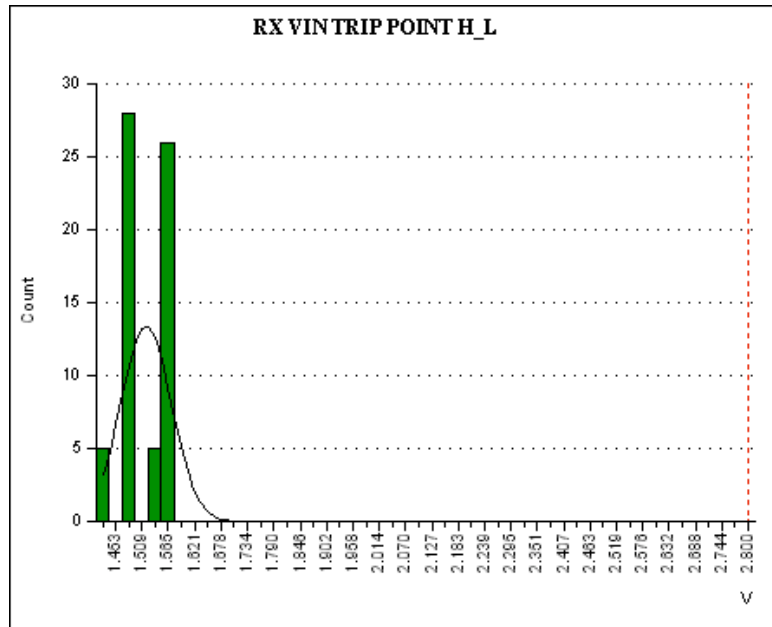
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.013, Test.Name=RX VIN TRIP POINT H_L



Statistics: (V)

Max	1.575	25%	1.475	SpecHigh	2.800
Mean	1.516	10%	1.475	SpecLow	N/A
Min	1.425	N	64	PctWithinSpec	100.00
Range	150.001E-03	Cp	N/A	c	
StdDev	53.360E-03	Cpl	N/A	PctDefSpec	0
W	0.7762	Cpu	>4.0000	NWithinSpec	64
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	1.575	Skew	-0.0164		
75%	1.575	Kurtosis	-1.5617		
Median	1.475				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

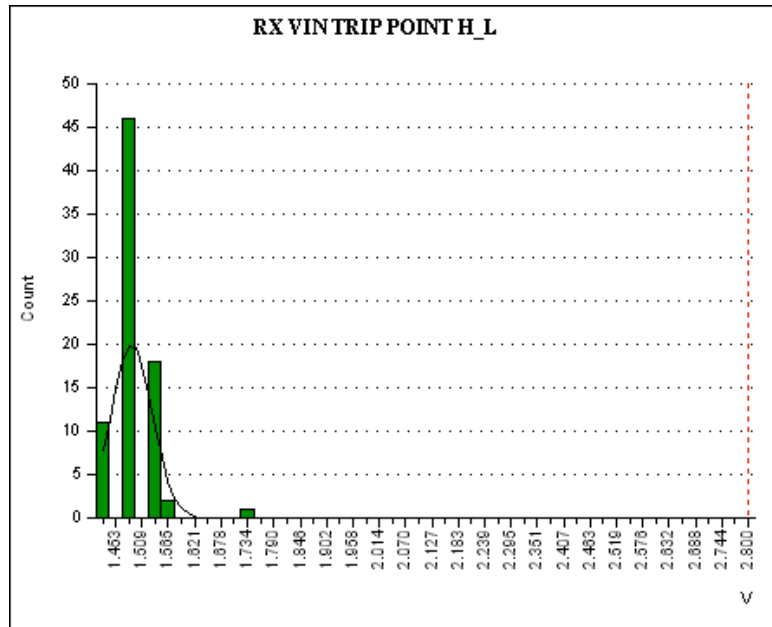
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=13.013, Test.Name=RX VIN TRIP POINT H_L



Statistics: (V)

Max	1.725	25%	1.475	SpecHigh	2.800
Mean	1.485	10%	1.425	SpecLow	N/A
Min	1.425	N	78	PctWithinSpec	100.00
Range	300.000E-03	Cp	N/A	PctDefSpec	0
StdDev	43.663E-03	Cpl	N/A	NWithinSpec	78
W	0.7263	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	1.525	Skew	2.2256		
75%	1.525	Kurtosis	10.8777		
Median	1.475				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

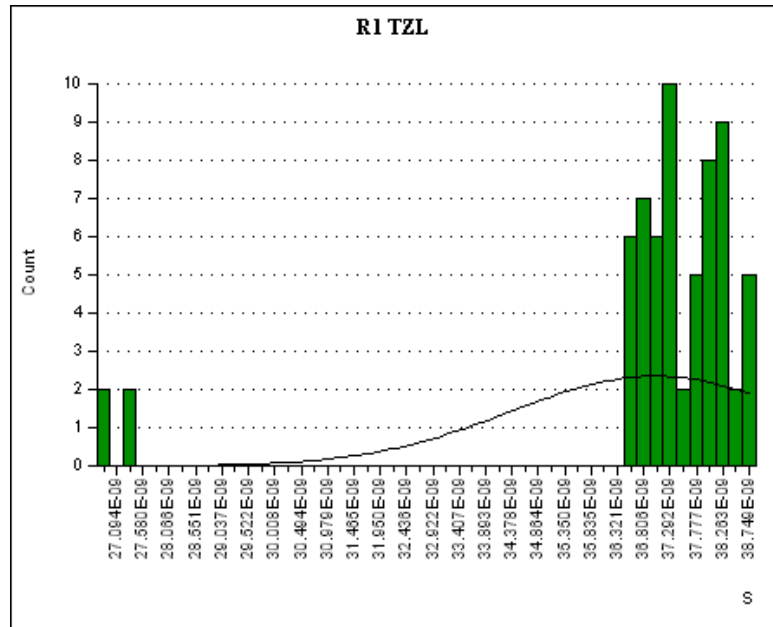
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=14.000, Test.Name=R1 TZL



Statistics: (S)

Max	38.749E-09	25%	36.895E-09	SpecHigh	N/A
Mean	36.923E-09	10%	36.523E-09	SpecLow	N/A
Min	26.852E-09	N	64	PctWithinSpec	N/A
Range	11.897E-09	Cp	N/A	c	
StdDev	2.637E-09	Cpl	N/A	PctDefSpec	N/A
W	0.4944	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	38.563E-09	Skew	-3.3210		
75%	38.098E-09	Kurtosis	10.3329		
Median	37.360E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

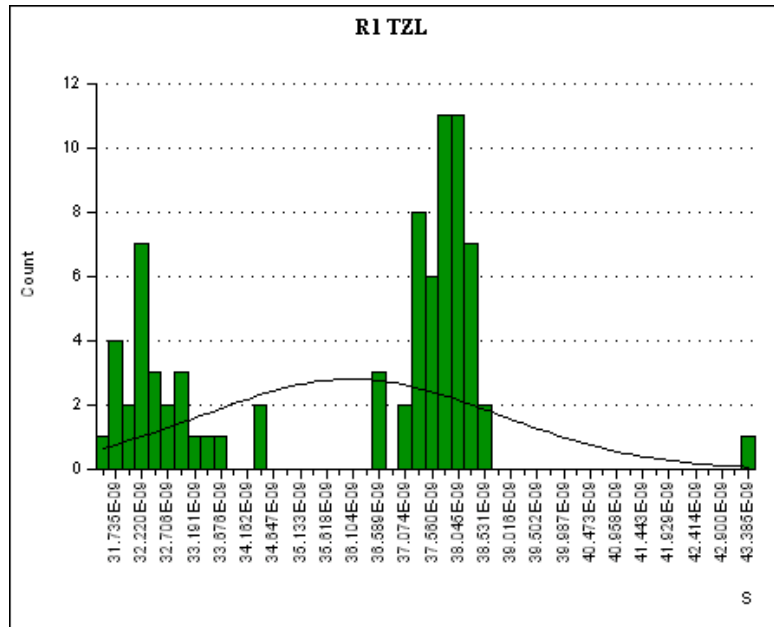
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.000, Test.Name=R1 TZL



Statistics: (S)

Max	43.385E-09	25%	32.908E-09	SpecHigh	N/A
Mean	36.034E-09	10%	32.153E-09	SpecLow	N/A
Min	31.492E-09	N	78	PctWithinSpec	N/A
Range	11.893E-09	Cp	N/A	PctDefSpec	N/A
StdDev	2.691E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8050	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	38.288E-09	Skew	-0.3887		
75%	38.005E-09	Kurtosis	-0.8583		
Median	37.344E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

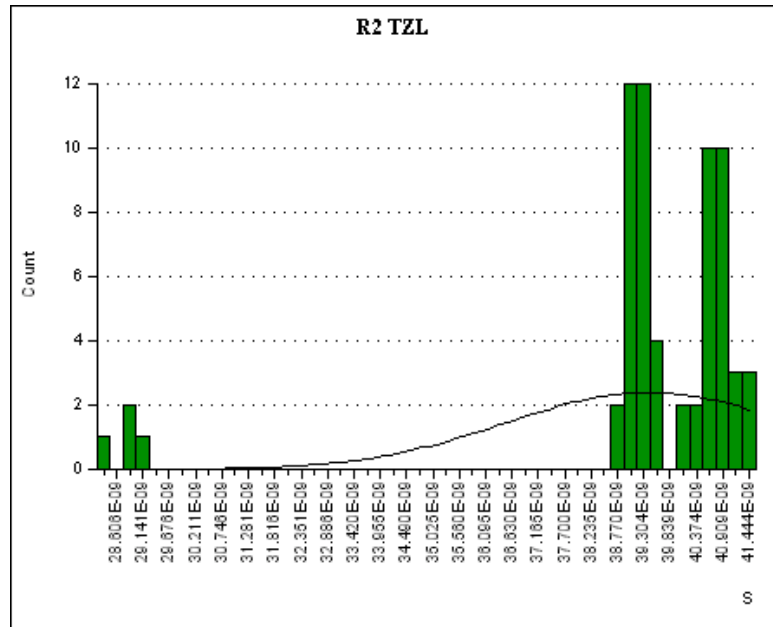
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.001, Test.Name=R2 TZL



Statistics: (S)

Max	41.444E-09	25%	39.126E-09	SpecHigh	N/A
Mean	39.290E-09	10%	38.940E-09	SpecLow	N/A
Min	28.339E-09	N	64	PctWithinSpec	N/A
Range	13.105E-09	Cp	N/A	PctDefSpec	N/A
StdDev	2.845E-09	Cpl	N/A	NWithinSpec	N/A
W	0.5259	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	40.886E-09	Skew	-3.1866		
75%	40.747E-09	Kurtosis	9.7339		
Median	39.545E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

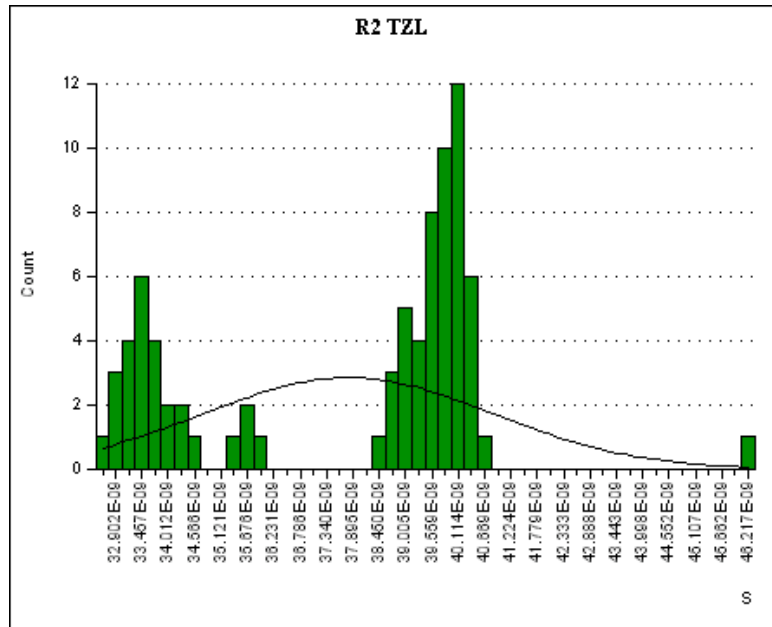
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.001, Test.Name=R2 TZL



Statistics: (S)

Max	46.217E-09	25%	34.041E-09	SpecHigh	N/A
Mean	37.758E-09	10%	33.285E-09	SpecLow	N/A
Min	32.625E-09	N	78	PctWithinSpec	N/A
Range	13.592E-09	Cp	N/A	PctDefSpec	N/A
StdDev	3.022E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8029	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	40.270E-09	Skew	-0.3807		
75%	39.987E-09	Kurtosis	-0.7683		
Median	39.326E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

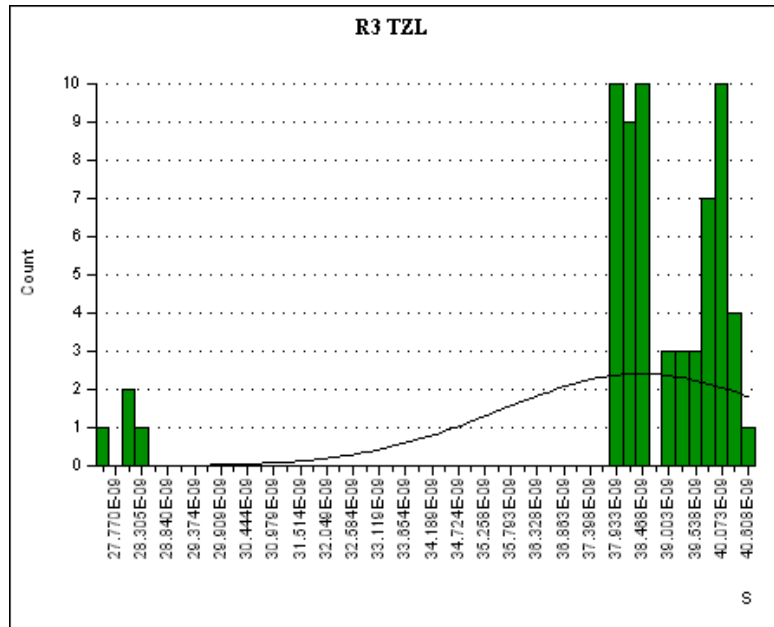
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.002, Test.Name=R3 TZL



Statistics: (S)

Max	40.608E-09	25%	38.103E-09	SpecHigh	N/A
Mean	38.334E-09	10%	37.824E-09	SpecLow	N/A
Min	27.502E-09	N	64	PctWithinSpec	N/A
Range	13.105E-09	Cp	N/A	c	
StdDev	2.835E-09	Cpl	N/A	PctDefSpec	N/A
W	0.5431	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	40.143E-09	Skew	-3.1240		
75%	39.864E-09	Kurtosis	9.4565		
Median	38.568E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

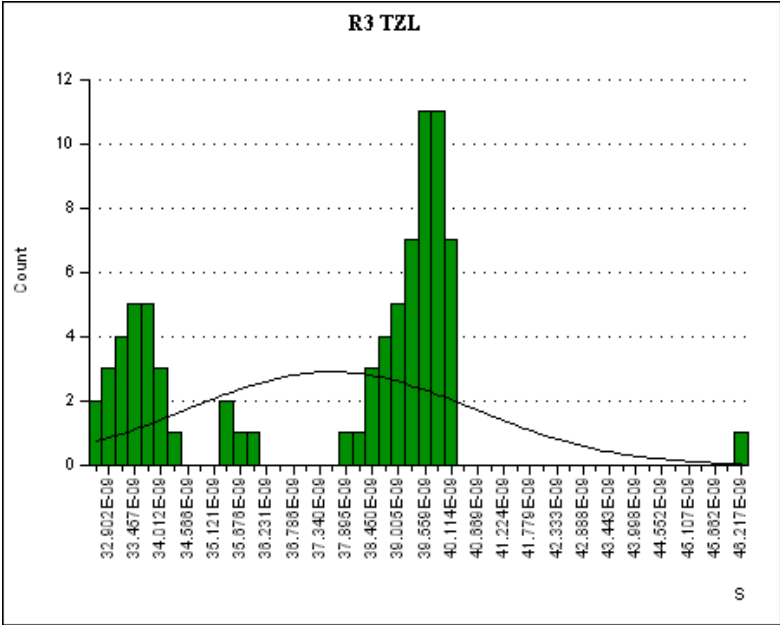
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.002, Test.Name=R3 TZL



Statistics: (S)

Max	46.217E-09	25%	33.946E-09	SpecHigh	N/A
Mean	37.535E-09	10%	33.097E-09	SpecLow	N/A
Min	32.625E-09	N	78	PctWithinSpec	N/A
Range	13.592E-09	Cp	N/A	c	
StdDev	2.960E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8047	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	39.987E-09	Skew	-0.3273		
75%	39.610E-09	Kurtosis	-0.6224		
Median	39.138E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

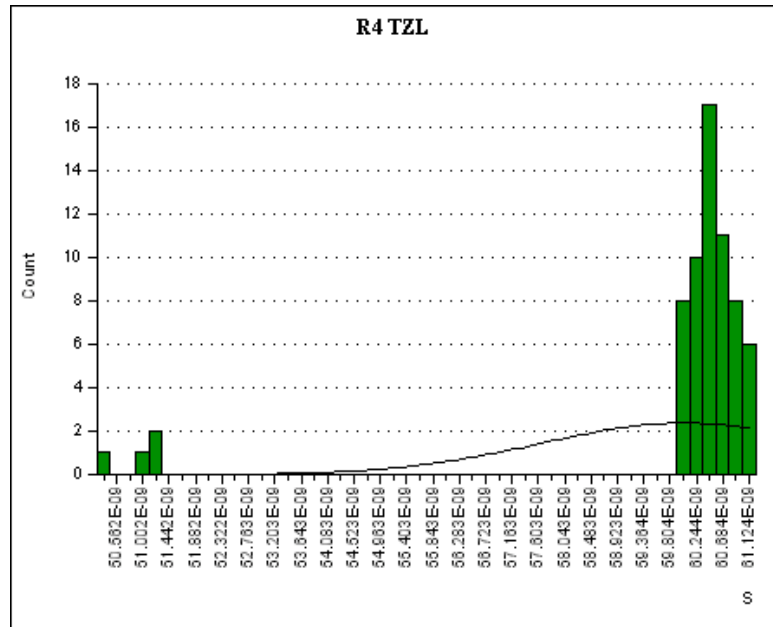
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=14.003, Test.Name=R4 TZL



Statistics: (S)

Max	61.124E-09	25%	60.198E-09	SpecHigh	N/A
Mean	59.944E-09	10%	60.105E-09	SpecLow	N/A
Min	50.342E-09	N	64	PctWithinSpec	N/A
Range	10.782E-09	Cp	N/A	PctDefSpec	N/A
StdDev	2.363E-09	Cpl	N/A	NWithinSpec	N/A
W	0.3804	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	60.942E-09	Skew	-3.6065		
75%	60.752E-09	Kurtosis	11.6870		
Median	60.522E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

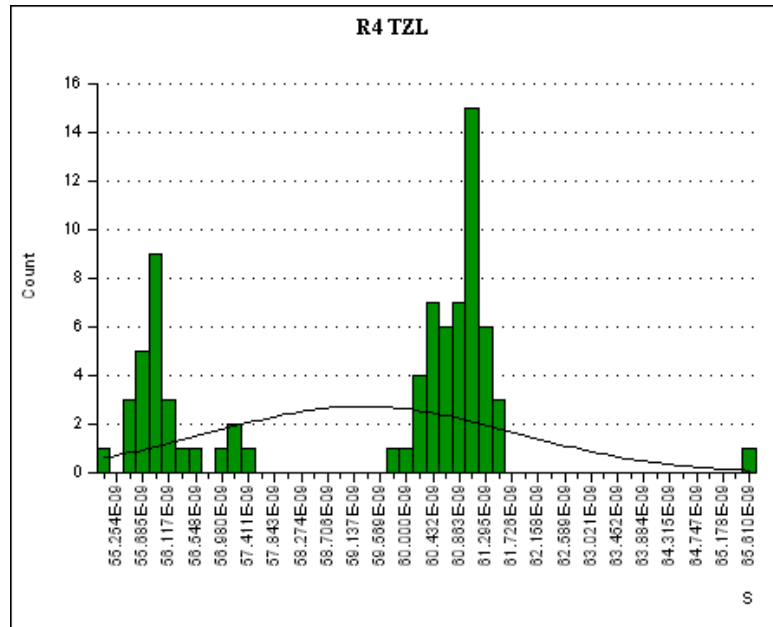
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.003, Test.Name=R4 TZL



Statistics: (S)

Max	65.610E-09	25%	56.171E-09	SpecHigh	N/A
Mean	59.237E-09	10%	55.699E-09	SpecLow	N/A
Min	55.038E-09	N	78	PctWithinSpec	N/A
Range	10.572E-09	Cp	N/A	c	
StdDev	2.449E-09	Cpl	N/A	PctDefSpec	N/A
W	0.7946	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	61.268E-09	Skew	-0.4217		
75%	61.079E-09	Kurtosis	-1.0075		
Median	60.512E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

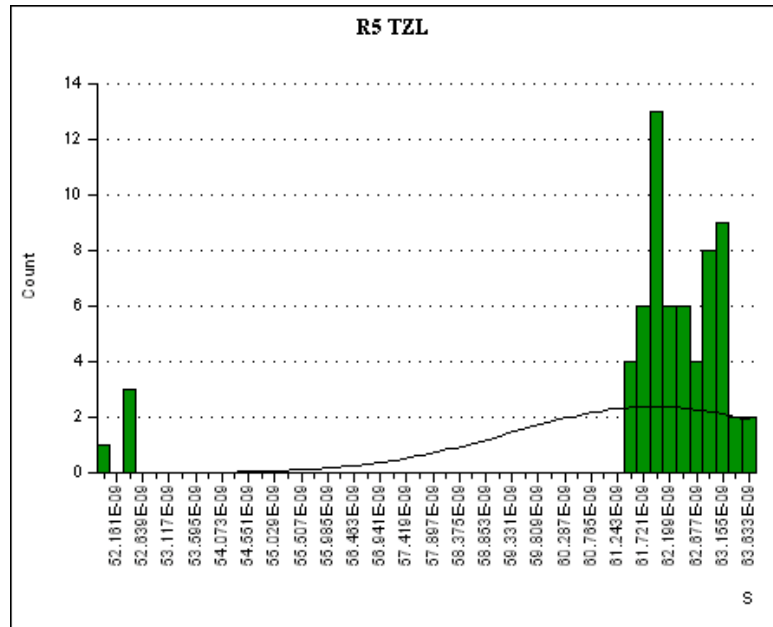
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.004, Test.Name=R5 TZL



Statistics: (S)

Max	63.633E-09	25%	61.872E-09	SpecHigh	N/A
Mean	61.811E-09	10%	61.593E-09	SpecLow	N/A
Min	51.922E-09	N	64	PctWithinSpec	N/A
Range	11.711E-09	Cp	N/A	c	
StdDev	2.560E-09	Cpl	N/A	PctDefSpec	N/A
W	0.4792	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	63.262E-09	Skew	-3.3624		
75%	62.983E-09	Kurtosis	10.5282		
Median	62.244E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

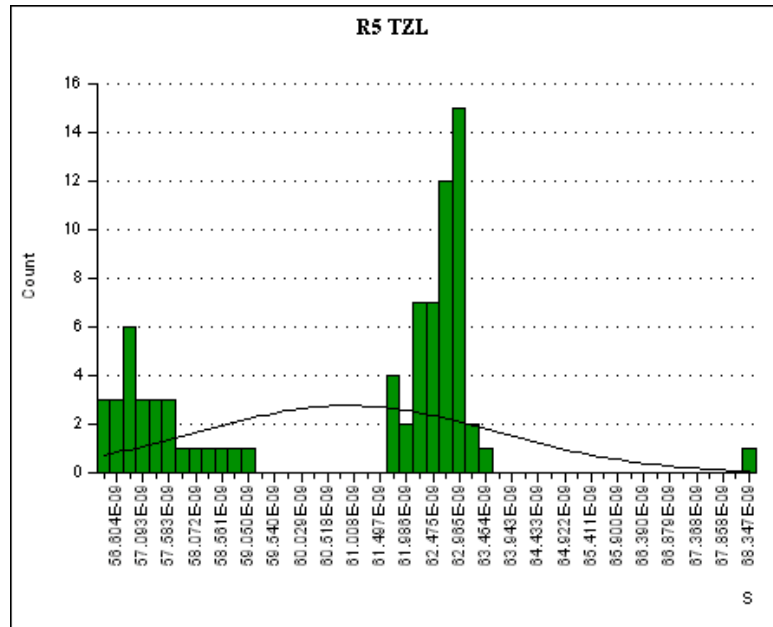
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.004, Test.Name=R5 TZL



Statistics: (S)

Max	68.347E-09	25%	57.492E-09	SpecHigh	N/A
Mean	60.846E-09	10%	56.737E-09	SpecLow	N/A
Min	56.359E-09	N	78	PctWithinSpec	N/A
Range	11.988E-09	Cp	N/A	PctDefSpec	N/A
StdDev	2.752E-09	Cpl	N/A	NWithinSpec	N/A
W	0.7918	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	63.061E-09	Skew	-0.4071		
75%	62.778E-09	Kurtosis	-0.8566		
Median	62.306E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

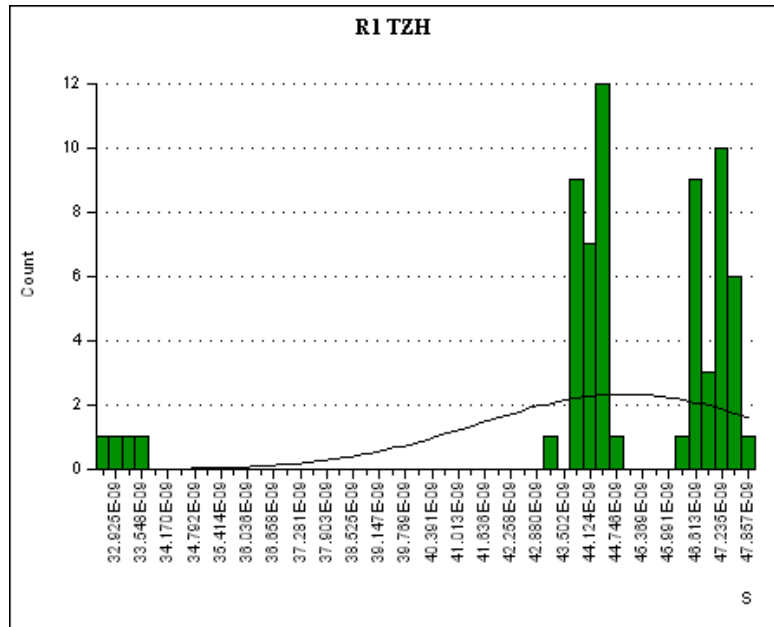
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.005, Test.Name=R1 TZh



Statistics: (S)

Max	47.857E-09	25%	44.054E-09	SpecHigh	N/A
Mean	44.810E-09	10%	43.682E-09	SpecLow	N/A
Min	32.614E-09	N	64	PctWithinSpec	N/A
Range	15.243E-09	Cp	N/A	c	
StdDev	3.387E-09	Cpl	N/A	PctDefSpec	N/A
W	0.6396	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	47.393E-09	Skew	-2.5997		
75%	47.114E-09	Kurtosis	7.1484		
Median	44.519E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

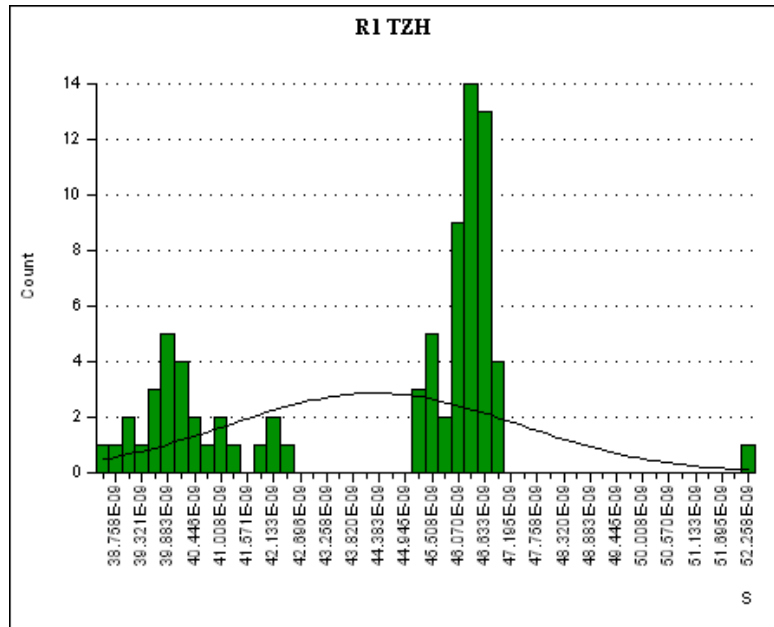
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.005, Test.Name=R1 TZh



Statistics: (S)

Max	52.258E-09	25%	40.742E-09	SpecHigh	N/A
Mean	44.227E-09	10%	39.610E-09	SpecLow	N/A
Min	38.477E-09	N	78	PctWithinSpec	N/A
Range	13.781E-09	Cp	N/A	c	
StdDev	3.048E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8015	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	46.689E-09	Skew	-0.4780		
75%	46.406E-09	Kurtosis	-0.8350		
Median	45.981E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

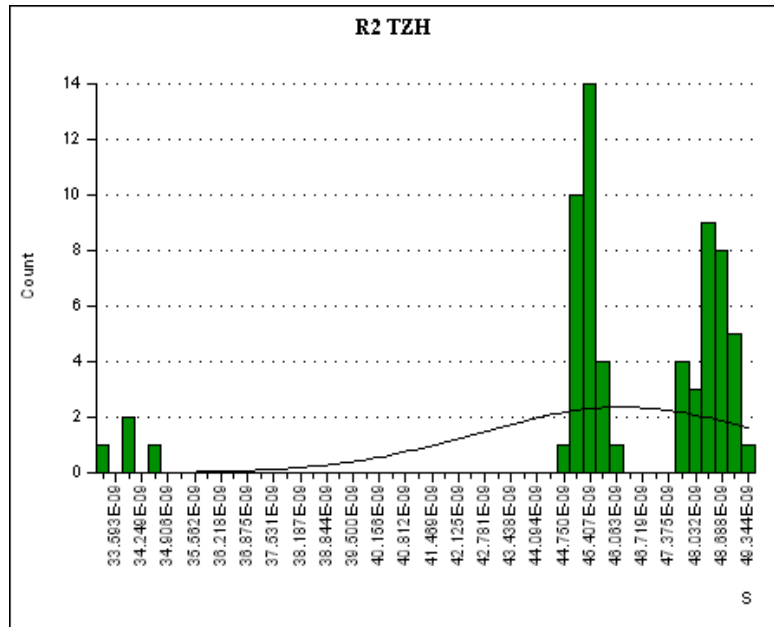
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.006, Test.Name=R2 TZh



Statistics: (S)

Max	49.344E-09	25%	45.263E-09	SpecHigh	N/A
Mean	46.089E-09	10%	45.077E-09	SpecLow	N/A
Min	33.265E-09	N	64	PctWithinSpec	N/A
Range	16.080E-09	Cp	N/A	PctDefSpec	N/A
StdDev	3.542E-09	Cpl	N/A	NWithinSpec	N/A
W	0.6427	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	48.787E-09	Skew	-2.5467		
75%	48.415E-09	Kurtosis	6.9456		
Median	45.727E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

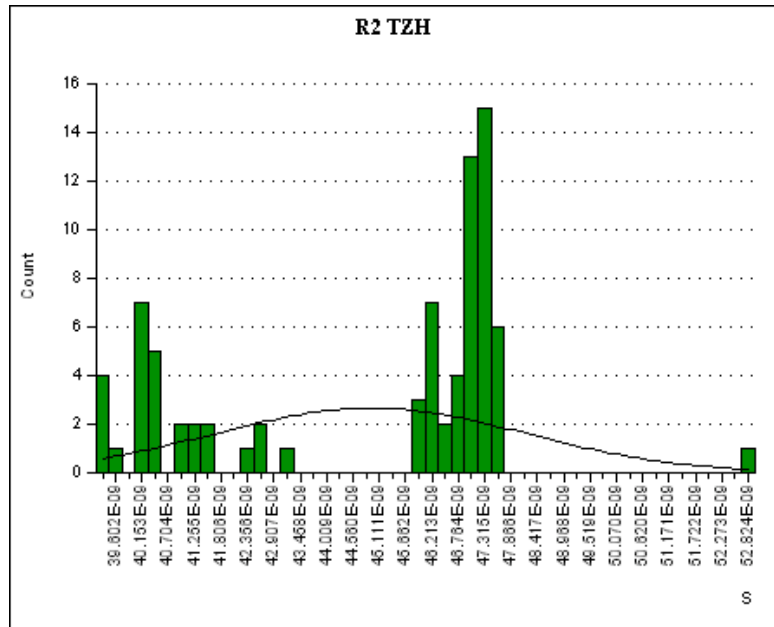
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.006, Test.Name=R2 TZh



Statistics: (S)

Max	52.824E-09	25%	41.214E-09	SpecHigh	N/A
Mean	44.889E-09	10%	40.081E-09	SpecLow	N/A
Min	39.326E-09	N	78	PctWithinSpec	N/A
Range	13.498E-09	Cp	N/A	PctDefSpec	N/A
StdDev	3.220E-09	Cpl	N/A	NWithinSpec	N/A
W	0.7963	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	47.444E-09	Skew	-0.5158		
75%	47.255E-09	Kurtosis	-0.9914		
Median	46.642E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

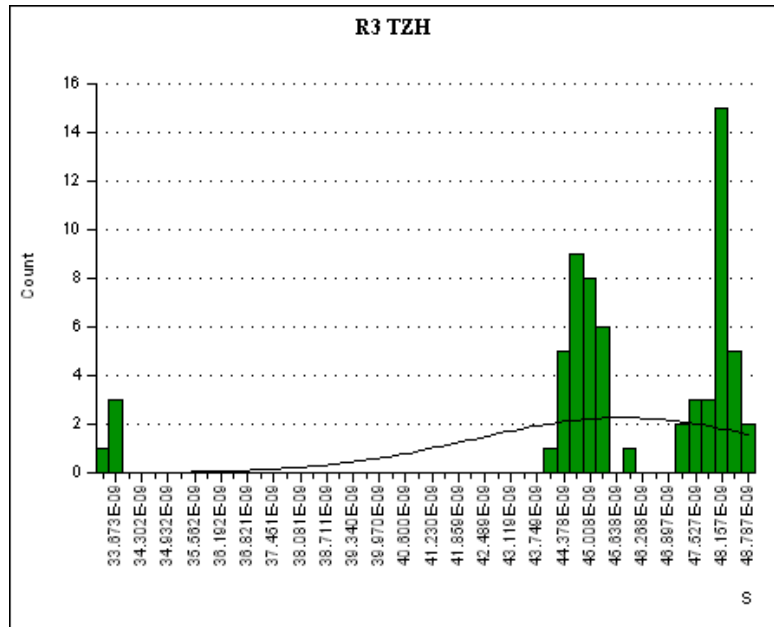
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.007, Test.Name=R3 TZH



Statistics: (S)

Max	48.787E-09	25%	44.751E-09	SpecHigh	N/A
Mean	45.664E-09	10%	44.240E-09	SpecLow	N/A
Min	33.358E-09	N	64	PctWithinSpec	N/A
Range	15.429E-09	Cp	N/A	PctDefSpec	N/A
StdDev	3.547E-09	Cpl	N/A	NWithinSpec	N/A
W	0.6556	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	48.322E-09	Skew	-2.4570		
75%	48.136E-09	Kurtosis	6.5114		
Median	45.356E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

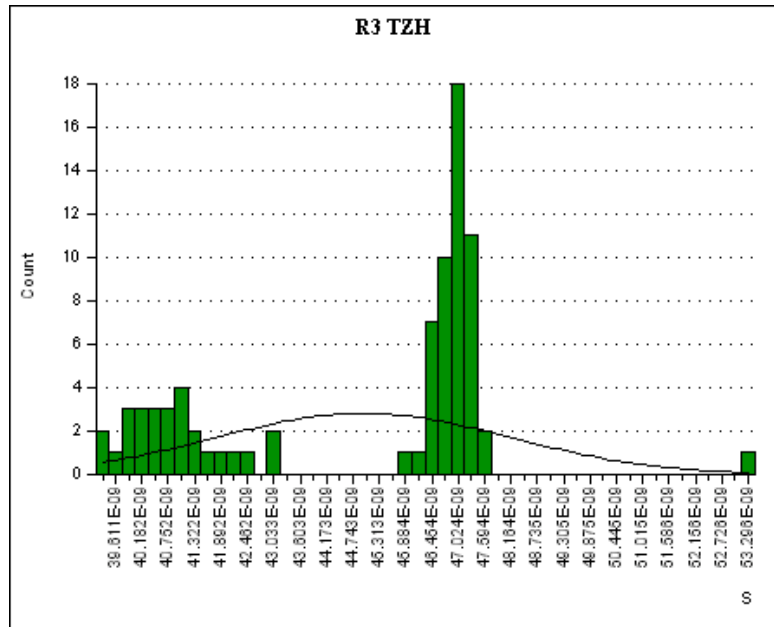
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.007, Test.Name=R3 TZh



Statistics: (S)

Max	53.296E-09	25%	41.403E-09	SpecHigh	N/A
Mean	44.922E-09	10%	40.176E-09	SpecLow	N/A
Min	39.326E-09	N	78	PctWithinSpec	N/A
Range	13.970E-09	Cp	N/A	c	
StdDev	3.140E-09	Cpl	N/A	PctDefSpec	N/A
W	0.7866	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	47.350E-09	Skew	-0.4667		
75%	47.066E-09	Kurtosis	-0.8376		
Median	46.736E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

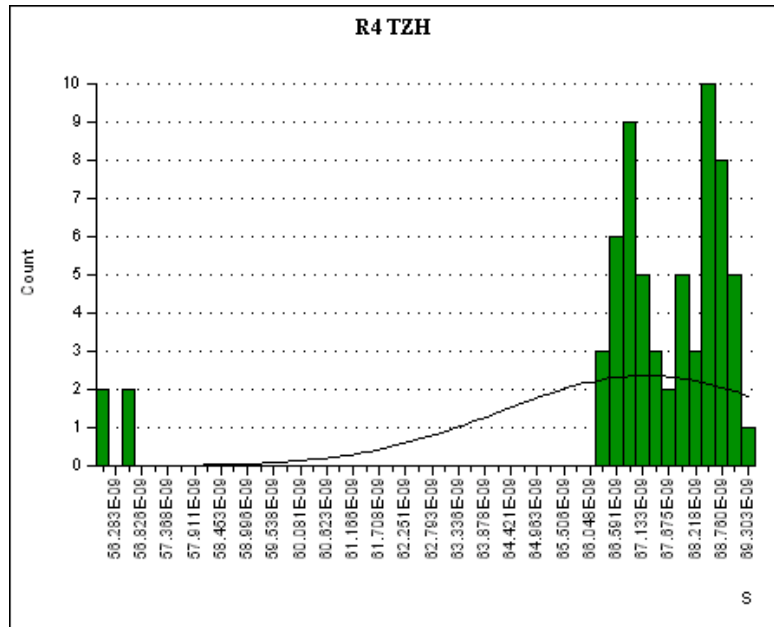
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.008, Test.Name=R4 TZh



Statistics: (S)

Max	69.303E-09	25%	66.846E-09	SpecHigh	N/A
Mean	67.074E-09	10%	66.428E-09	SpecLow	N/A
Min	56.012E-09	N	64	PctWithinSpec	N/A
Range	13.291E-09	Cp	N/A	c	
StdDev	2.933E-09	Cpl	N/A	PctDefSpec	N/A
W	0.5398	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	68.838E-09	Skew	-3.1622		
75%	68.513E-09	Kurtosis	9.5939		
Median	67.776E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

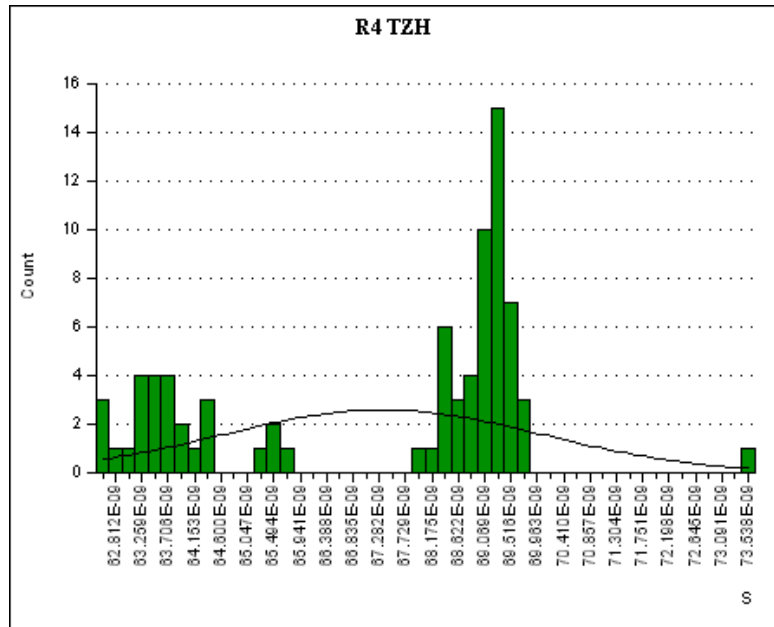
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.008, Test.Name=R4 TZh



Statistics: (S)

Max	73.538E-09	25%	64.194E-09	SpecHigh	N/A
Mean	67.294E-09	10%	63.250E-09	SpecLow	N/A
Min	62.589E-09	N	78	PctWithinSpec	N/A
Range	10.949E-09	Cp	N/A	PctDefSpec	N/A
StdDev	2.679E-09	Cpl	N/A	NWithinSpec	N/A
W	0.7975	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	69.480E-09	Skew	-0.5478		
75%	69.196E-09	Kurtosis	-1.0763		
Median	68.819E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

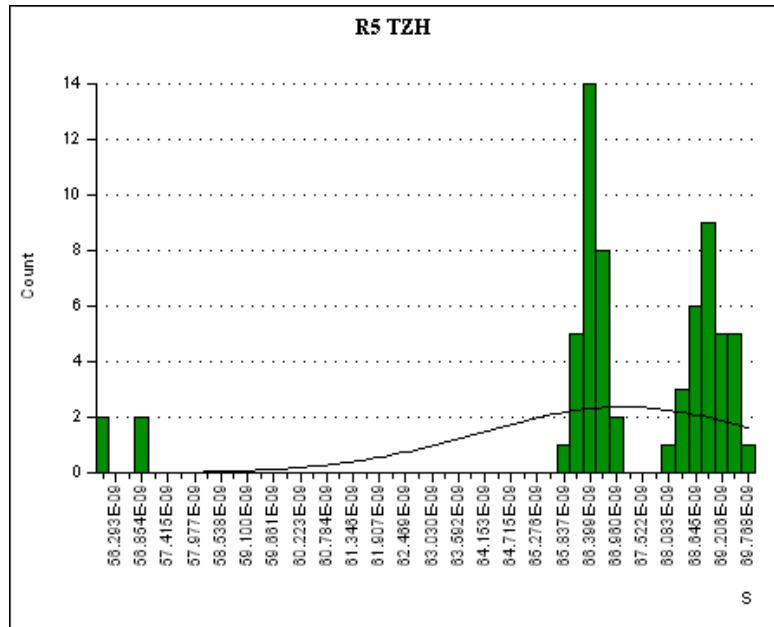
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.009, Test.Name=R5 TZh



Statistics: (S)

Max	69.768E-09	25%	66.428E-09	SpecHigh	N/A
Mean	67.001E-09	10%	66.056E-09	SpecLow	N/A
Min	56.012E-09	N	64	PctWithinSpec	N/A
Range	13.756E-09	Cp	N/A	PctDefSpec	N/A
StdDev	3.026E-09	Cpl	N/A	NWithinSpec	N/A
W	0.6326	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	69.303E-09	Skew	-2.6609		
75%	68.931E-09	Kurtosis	7.4404		
Median	66.846E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

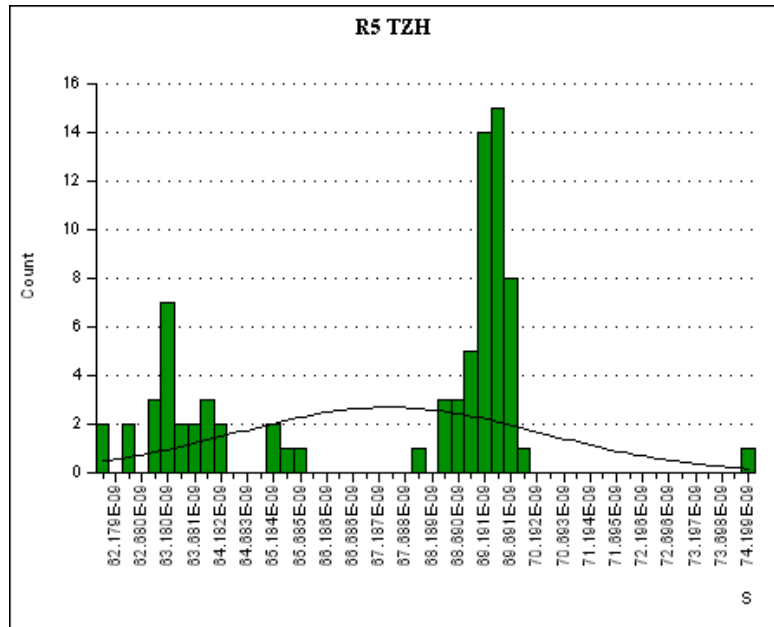
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.009, Test.Name=R5 TZh



Statistics: (S)

Max	74.199E-09	25%	64.005E-09	SpecHigh	N/A
Mean	67.317E-09	10%	63.061E-09	SpecLow	N/A
Min	61.928E-09	N	78	PctWithinSpec	N/A
Range	12.271E-09	Cp	N/A	PctDefSpec	N/A
StdDev	2.893E-09	Cpl	N/A	NWithinSpec	N/A
W	0.7910	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	69.574E-09	Skew	-0.5525		
75%	69.385E-09	Kurtosis	-1.0237		
Median	69.055E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

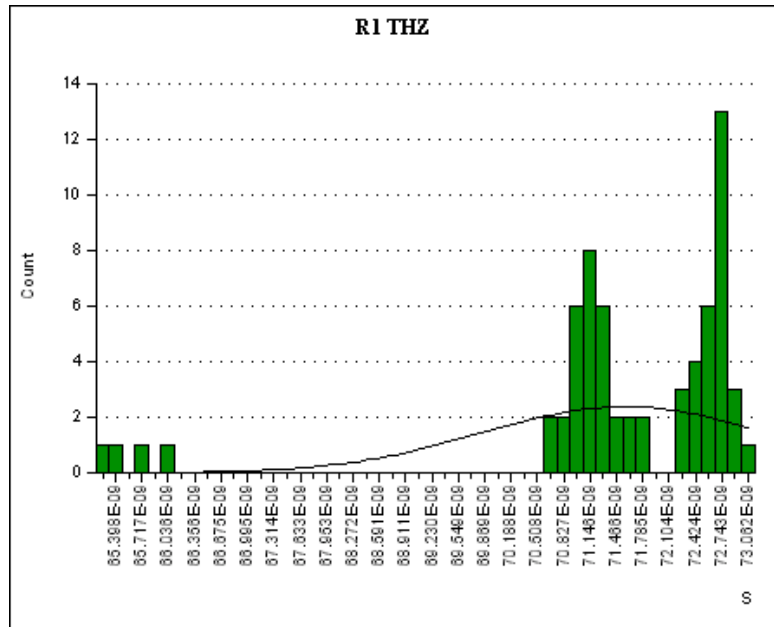
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.010, Test.Name=R1 THZ



Statistics: (S)

Max	73.062E-09	25%	71.140E-09	SpecHigh	N/A
Mean	71.511E-09	10%	70.815E-09	SpecLow	N/A
Min	65.238E-09	N	64	PctWithinSpec	N/A
Range	7.824E-09	Cp	N/A	PctDefSpec	N/A
StdDev	1.713E-09	Cpl	N/A	NWithinSpec	N/A
W	0.6632	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	72.784E-09	Skew	-2.5571		
75%	72.691E-09	Kurtosis	6.9545		
Median	71.651E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

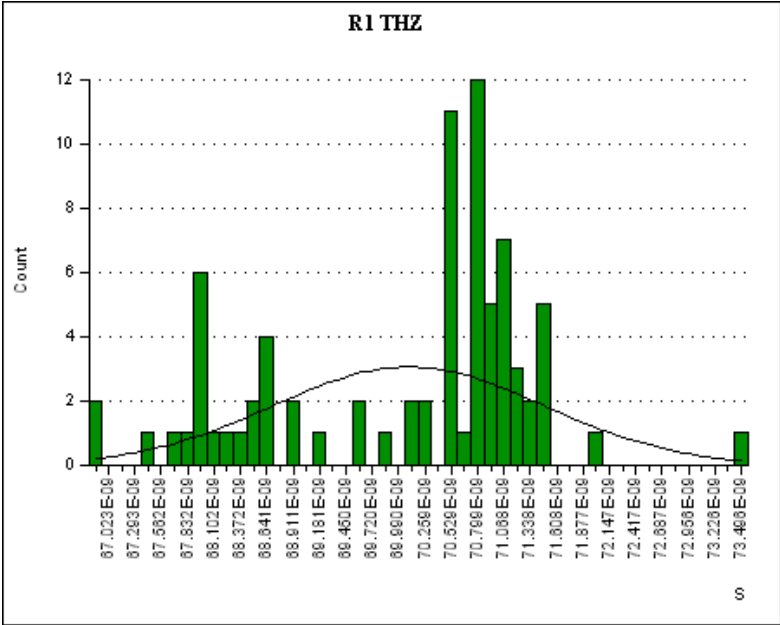
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.010, Test.Name=R1 THZ



Statistics: (S)

Max	73.496E-09	25%	68.682E-09	SpecHigh	N/A
Mean	70.061E-09	10%	67.927E-09	SpecLow	N/A
Min	66.888E-09	N	78	PctWithinSpec	N/A
Range	6.607E-09	Cp	N/A	c	
StdDev	1.368E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8868	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	71.325E-09	Skew	-0.6153		
75%	70.947E-09	Kurtosis	-0.3504		
Median	70.570E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

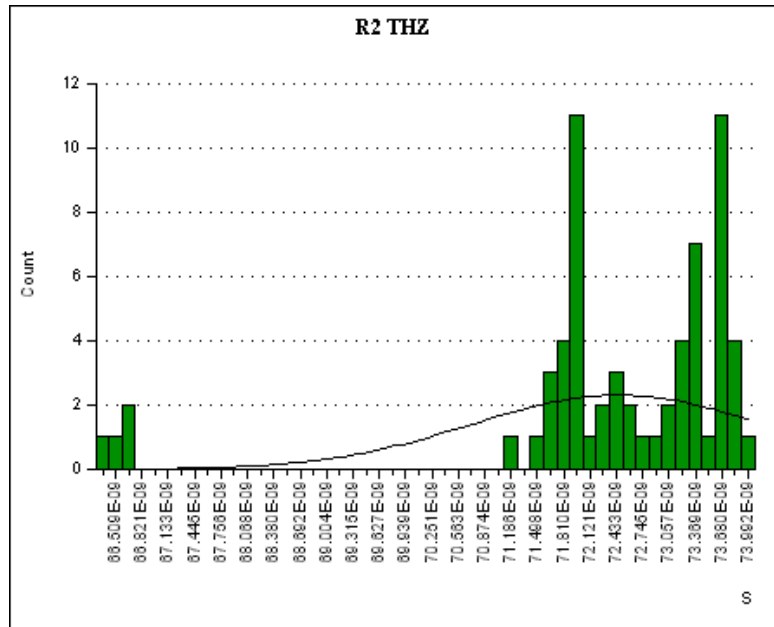
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=14.011, Test.Name=R2 THZ



Statistics: (S)

Max	73.992E-09	25%	71.930E-09	SpecHigh	N/A
Mean	72.407E-09	10%	71.651E-09	SpecLow	N/A
Min	66.353E-09	N	64	PctWithinSpec	N/A
Range	7.639E-09	Cp	N/A	c	
StdDev	1.724E-09	Cpl	N/A	PctDefSpec	N/A
W	0.6811	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	73.713E-09	Skew	-2.4755		
75%	73.574E-09	Kurtosis	6.5345		
Median	72.674E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

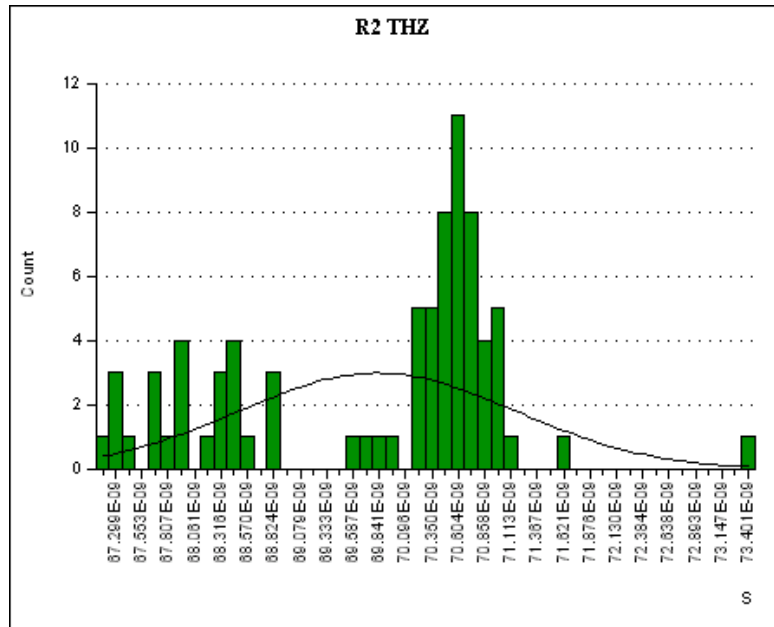
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.011, Test.Name=R2 THZ



Statistics: (S)

Max	73.401E-09	25%	68.493E-09	SpecHigh	N/A
Mean	69.797E-09	10%	67.738E-09	SpecLow	N/A
Min	67.171E-09	N	78	PctWithinSpec	N/A
Range	6.230E-09	Cp	N/A	PctDefSpec	N/A
StdDev	1.318E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8670	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	70.947E-09	Skew	-0.4808		
75%	70.758E-09	Kurtosis	-0.4665		
Median	70.428E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

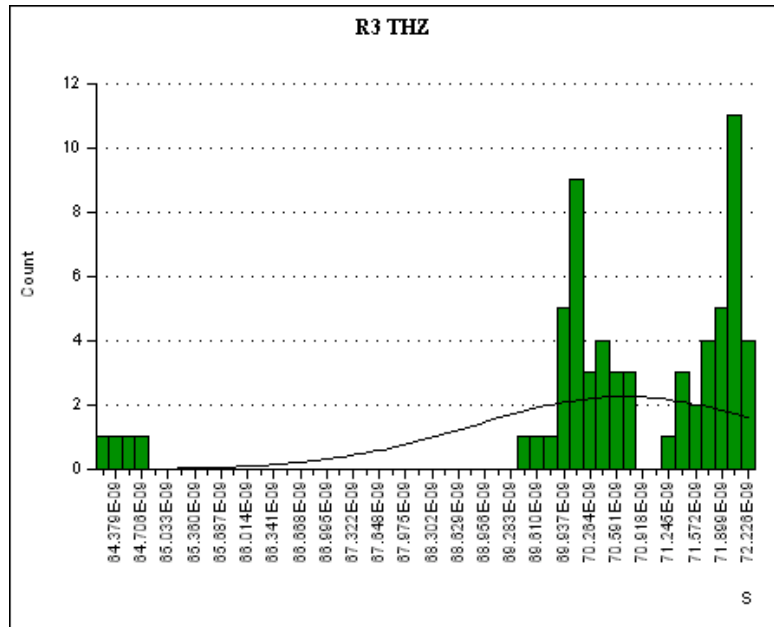
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.012, Test.Name=R3 THZ



Statistics: (S)

Max	72.226E-09	25%	70.071E-09	SpecHigh	N/A
Mean	70.628E-09	10%	69.699E-09	SpecLow	N/A
Min	64.216E-09	N	64	PctWithinSpec	N/A
Range	8.010E-09	Cp	N/A	PctDefSpec	N/A
StdDev	1.843E-09	Cpl	N/A	NWithinSpec	N/A
W	0.6969	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	72.133E-09	Skew	-2.3406		
75%	71.947E-09	Kurtosis	6.0233		
Median	70.722E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

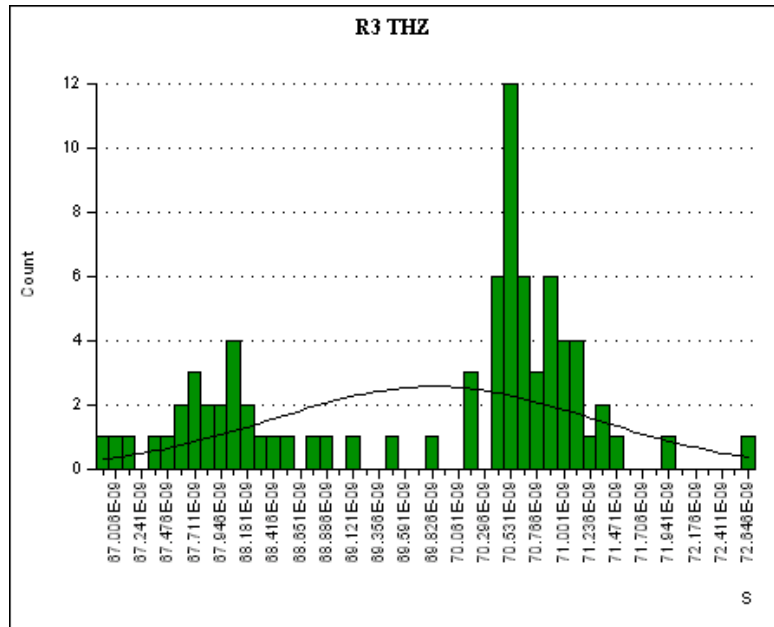
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.012, Test.Name=R3 THZ



Statistics: (S)

Max	72.646E-09	25%	68.210E-09	SpecHigh	N/A
Mean	69.810E-09	10%	67.738E-09	SpecLow	N/A
Min	66.888E-09	N	78	PctWithinSpec	N/A
Range	5.758E-09	Cp	N/A	PctDefSpec	N/A
StdDev	1.418E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8702	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	71.136E-09	Skew	-0.5915		
75%	70.853E-09	Kurtosis	-0.9765		
Median	70.475E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

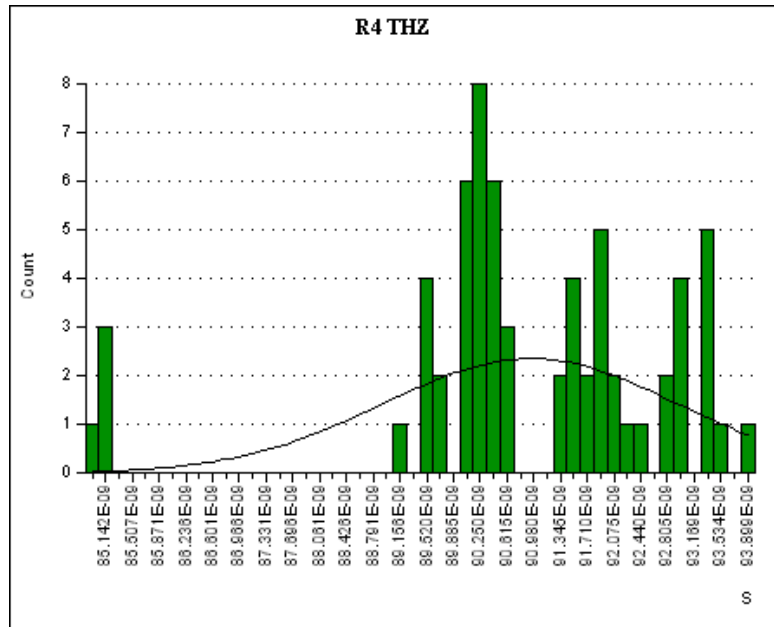
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.013, Test.Name=R4 THZ



Statistics: (S)

Max	93.899E-09	25%	90.071E-09	SpecHigh	N/A
Mean	90.873E-09	10%	89.513E-09	SpecLow	N/A
Min	84.959E-09	N	64	PctWithinSpec	N/A
Range	8.940E-09	Cp	N/A	PctDefSpec	N/A
StdDev	1.983E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8586	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	93.341E-09	Skew	-1.2862		
75%	92.040E-09	Kurtosis	2.6051		
Median	90.536E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

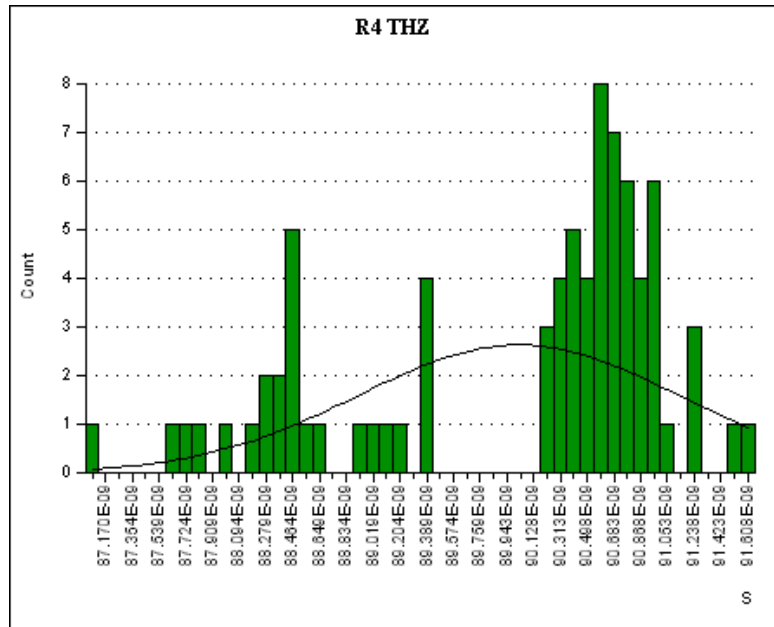
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.013, Test.Name=R4 THZ



Statistics: (S)

Max	91.608E-09	25%	89.154E-09	SpecHigh	N/A
Mean	89.996E-09	10%	88.304E-09	SpecLow	N/A
Min	87.077E-09	N	78	PctWithinSpec	N/A
Range	4.531E-09	Cp	N/A	c	
StdDev	1.093E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8622	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	90.947E-09	Skew	-0.8947		
75%	90.758E-09	Kurtosis	-0.4262		
Median	90.475E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

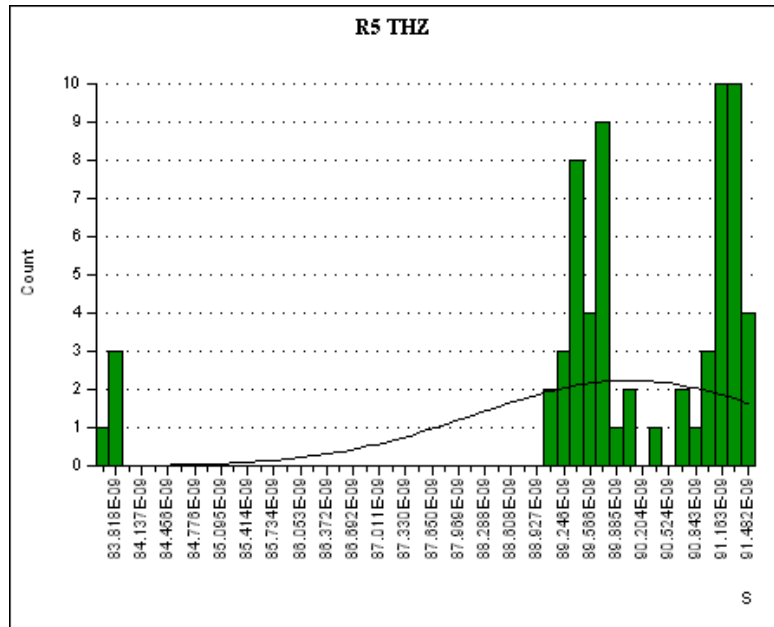
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.014, Test.Name=R5 THZ



Statistics: (S)

Max	91.482E-09	25%	89.421E-09	SpecHigh	N/A
Mean	89.969E-09	10%	89.235E-09	SpecLow	N/A
Min	83.658E-09	N	64	PctWithinSpec	N/A
Range	7.824E-09	Cp	N/A	c	
StdDev	1.819E-09	Cpl	N/A	PctDefSpec	N/A
W	0.6704	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	91.389E-09	Skew	-2.4359		
75%	91.203E-09	Kurtosis	6.3922		
Median	90.025E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

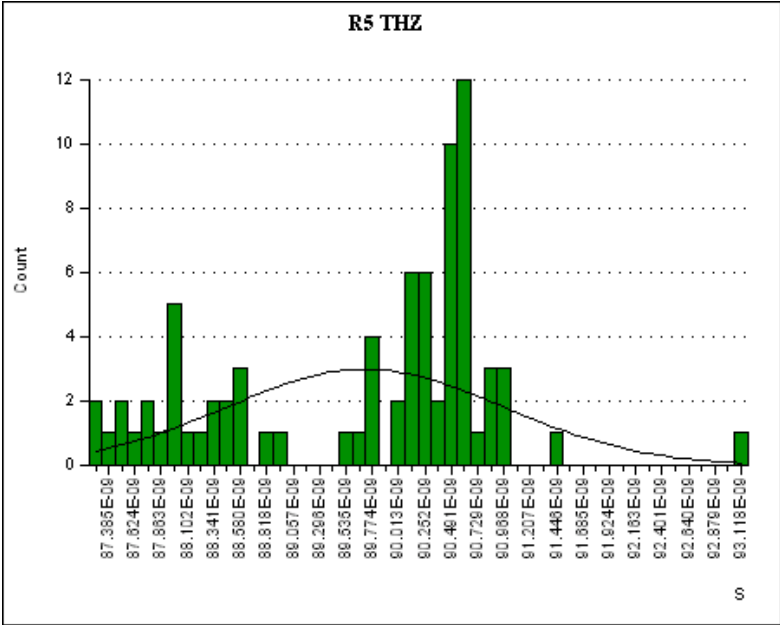
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.014, Test.Name=R5 THZ



Statistics: (S)

Max	93.118E-09	25%	88.493E-09	SpecHigh	N/A
Mean	89.689E-09	10%	87.738E-09	SpecLow	N/A
Min	87.266E-09	N	78	PctWithinSpec	N/A
Range	5.852E-09	Cp	N/A	c	
StdDev	1.243E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8798	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	90.853E-09	Skew	-0.4398		
75%	90.570E-09	Kurtosis	-0.4732		
Median	90.239E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

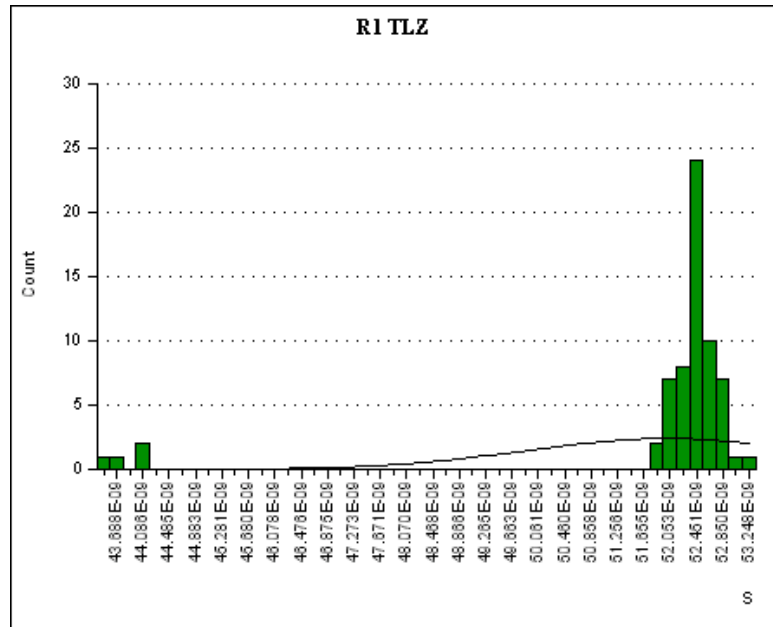
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=14.015, Test.Name=R1 TLZ



Statistics: (S)

Max	53.248E-09	25%	52.236E-09	SpecHigh	N/A
Mean	51.927E-09	10%	52.040E-09	SpecLow	N/A
Min	43.489E-09	N	64	PctWithinSpec	N/A
Range	9.759E-09	Cp	N/A	c	
StdDev	2.117E-09	Cpl	N/A	PctDefSpec	N/A
W	0.3753	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	52.794E-09	Skew	-3.6090		
75%	52.597E-09	Kurtosis	11.6776		
Median	52.463E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

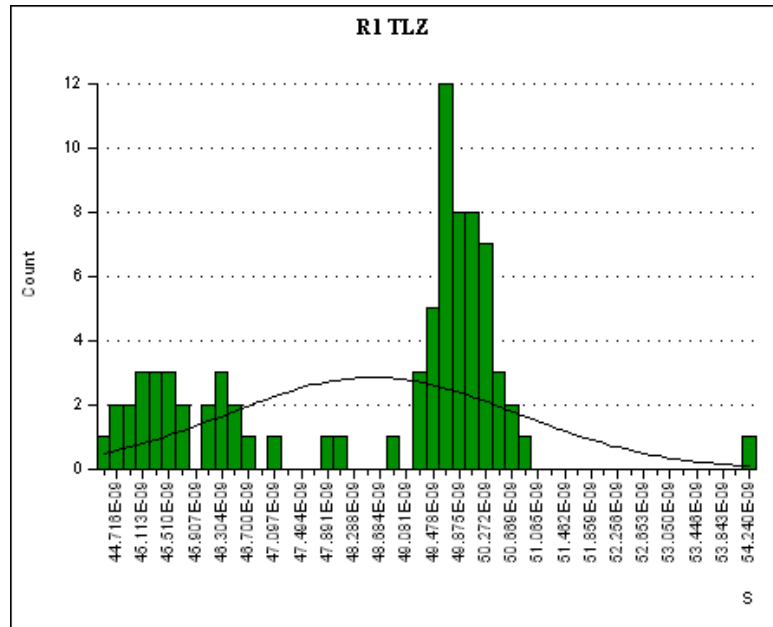
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.015, Test.Name=R1 TLZ



Statistics: (S)

Max	54.240E-09	25%	46.311E-09	SpecHigh	N/A
Mean	48.535E-09	10%	45.179E-09	SpecLow	N/A
Min	44.518E-09	N	78	PctWithinSpec	N/A
Range	9.722E-09	Cp	N/A	PctDefSpec	N/A
StdDev	2.155E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8369	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	50.370E-09	Skew	-0.4871		
75%	49.992E-09	Kurtosis	-0.7204		
Median	49.615E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

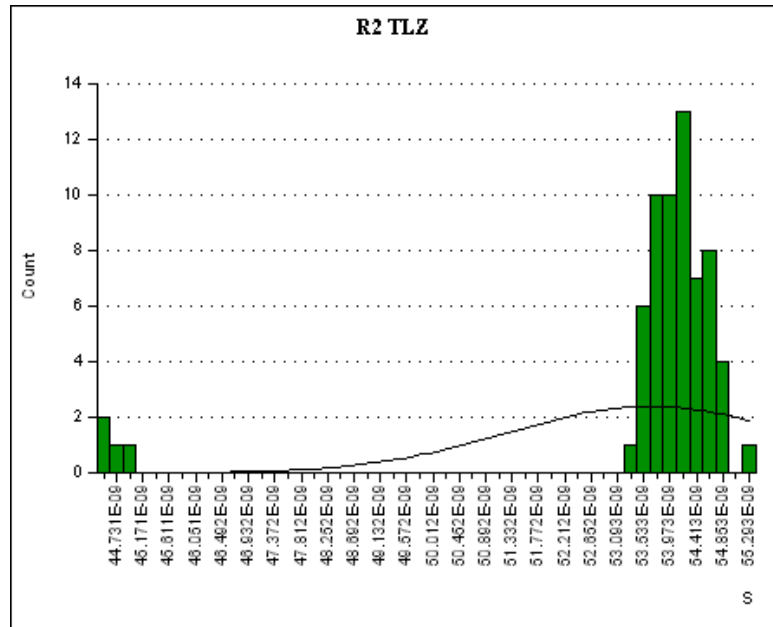
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.016, Test.Name=R2 TLZ



Statistics: (S)

Max	55.293E-09	25%	53.765E-09	SpecHigh	N/A
Mean	53.552E-09	10%	53.537E-09	SpecLow	N/A
Min	44.511E-09	N	64	PctWithinSpec	N/A
Range	10.782E-09	Cp	N/A	PctDefSpec	N/A
StdDev	2.345E-09	Cpl	N/A	NWithinSpec	N/A
W	0.4211	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	54.642E-09	Skew	-3.5195		
75%	54.363E-09	Kurtosis	11.2496		
Median	54.085E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

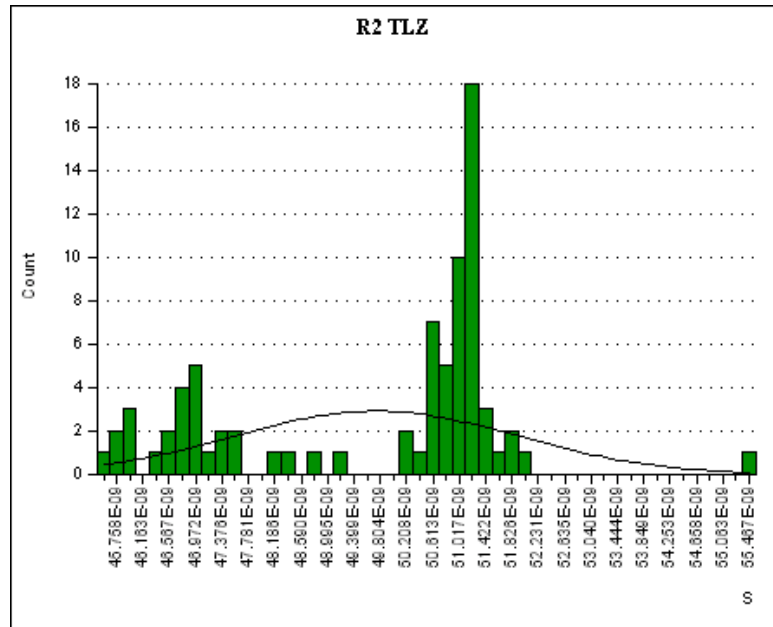
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.016, Test.Name=R2 TLZ



Statistics: (S)

Max	55.467E-09	25%	47.444E-09	SpecHigh	N/A
Mean	49.703E-09	10%	46.500E-09	SpecLow	N/A
Min	45.556E-09	N	78	PctWithinSpec	N/A
Range	9.911E-09	Cp	N/A	PctDefSpec	N/A
StdDev	2.150E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8304	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	51.408E-09	Skew	-0.4907		
75%	51.220E-09	Kurtosis	-0.6713		
Median	50.842E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

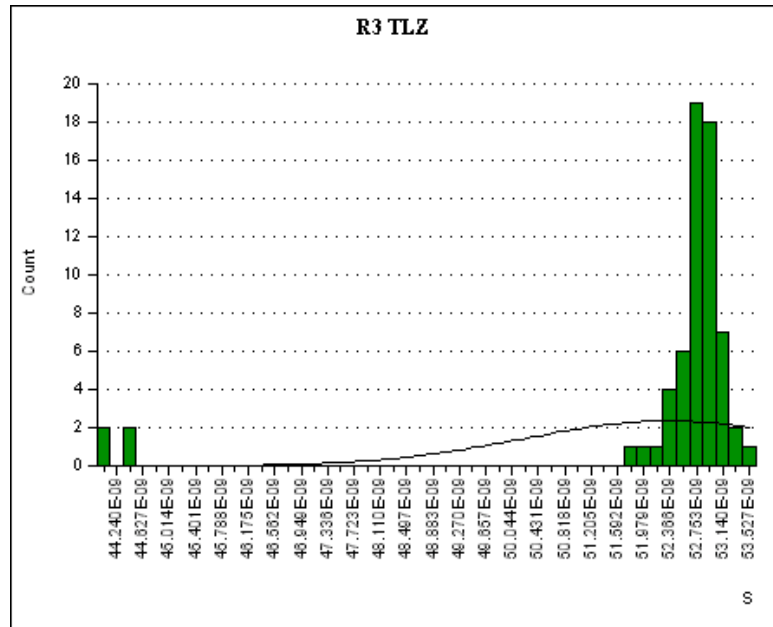
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.017, Test.Name=R3 TLZ



Statistics: (S)

Max	53.527E-09	25%	52.603E-09	SpecHigh	N/A
Mean	52.264E-09	10%	52.226E-09	SpecLow	N/A
Min	44.047E-09	N	64	PctWithinSpec	N/A
Range	9.480E-09	Cp	N/A	c	
StdDev	2.092E-09	Cpl	N/A	PctDefSpec	N/A
W	0.3821	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	53.155E-09	Skew	-3.5892		
75%	52.928E-09	Kurtosis	11.5656		
Median	52.794E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

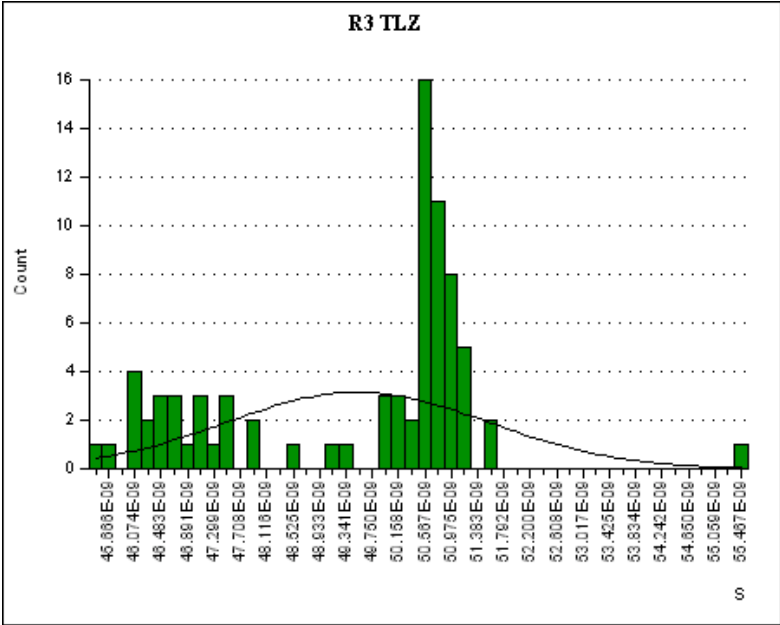
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.017, Test.Name=R3 TLZ



Statistics: (S)

Max	55.467E-09	25%	47.538E-09	SpecHigh	N/A
Mean	49.487E-09	10%	46.311E-09	SpecLow	N/A
Min	45.462E-09	N	78	PctWithinSpec	N/A
Range	10.005E-09	Cp	N/A	c	
StdDev	2.014E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8368	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	51.125E-09	Skew	-0.4227		
75%	50.842E-09	Kurtosis	-0.2756		
Median	50.464E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

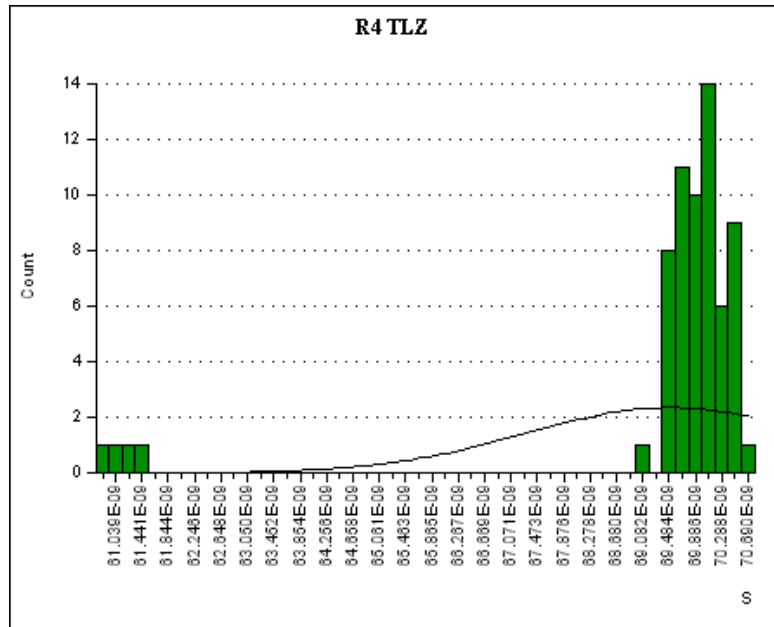
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=14.018, Test.Name=R4 TLZ



Statistics: (S)

Max	70.690E-09	25%	69.673E-09	SpecHigh	N/A
Mean	69.430E-09	10%	69.399E-09	SpecLow	N/A
Min	60.838E-09	N	64	PctWithinSpec	N/A
Range	9.852E-09	Cp	N/A	PctDefSpec	N/A
StdDev	2.183E-09	Cpl	N/A	NWithinSpec	N/A
W	0.4014	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	70.422E-09	Skew	-3.5617		
75%	70.184E-09	Kurtosis	11.4446		
Median	69.952E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

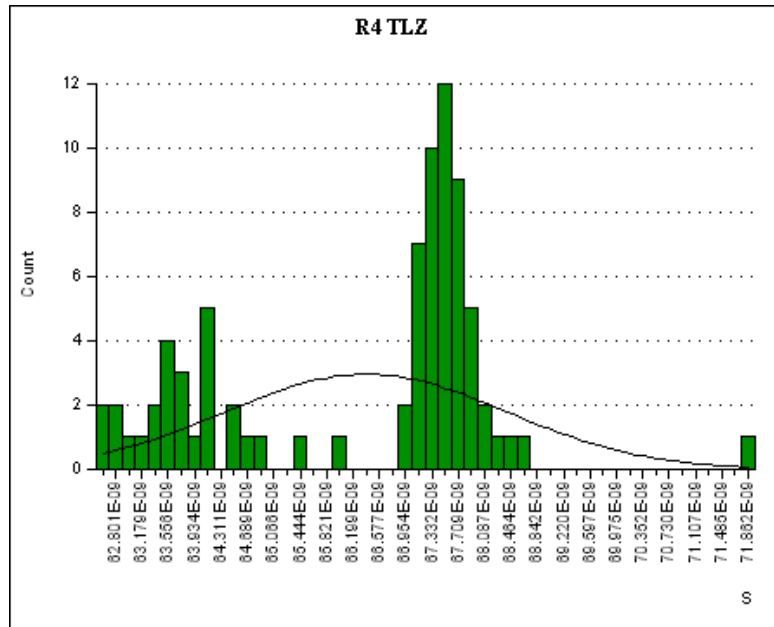
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.018, Test.Name=R4 TLZ



Statistics: (S)

Max	71.862E-09	25%	64.122E-09	SpecHigh	N/A
Mean	66.355E-09	10%	63.367E-09	SpecLow	N/A
Min	62.612E-09	N	78	PctWithinSpec	N/A
Range	9.250E-09	Cp	N/A	PctDefSpec	N/A
StdDev	1.982E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8378	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	67.992E-09	Skew	-0.4451		
75%	67.709E-09	Kurtosis	-0.5816		
Median	67.426E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

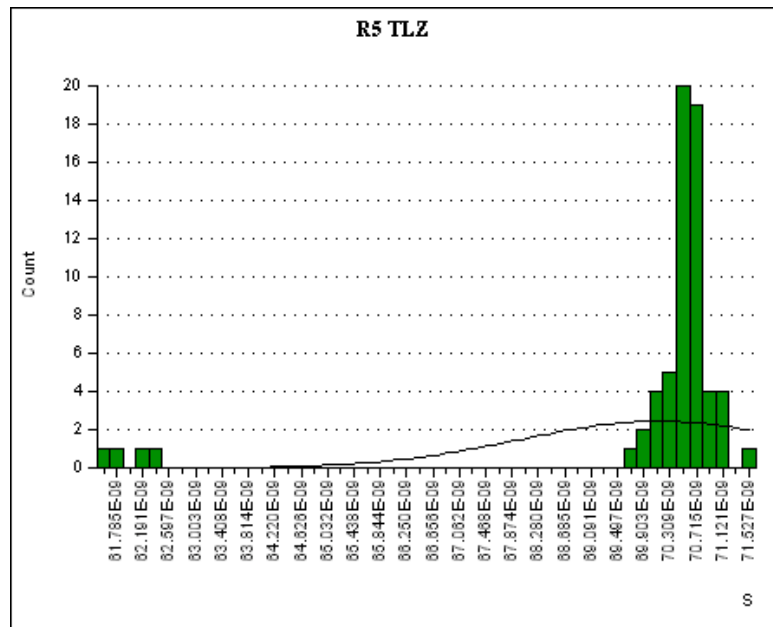
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.019, Test.Name=R5 TLZ



Statistics: (S)

Max	71.527E-09	25%	70.370E-09	SpecHigh	N/A
Mean	70.050E-09	10%	69.947E-09	SpecLow	N/A
Min	61.582E-09	N	64	PctWithinSpec	N/A
Range	9.945E-09	Cp	N/A	PctDefSpec	N/A
StdDev	2.118E-09	Cpl	N/A	NWithinSpec	N/A
W	0.3908	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	70.969E-09	Skew	-3.5842		
75%	70.701E-09	Kurtosis	11.5777		
Median	70.597E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

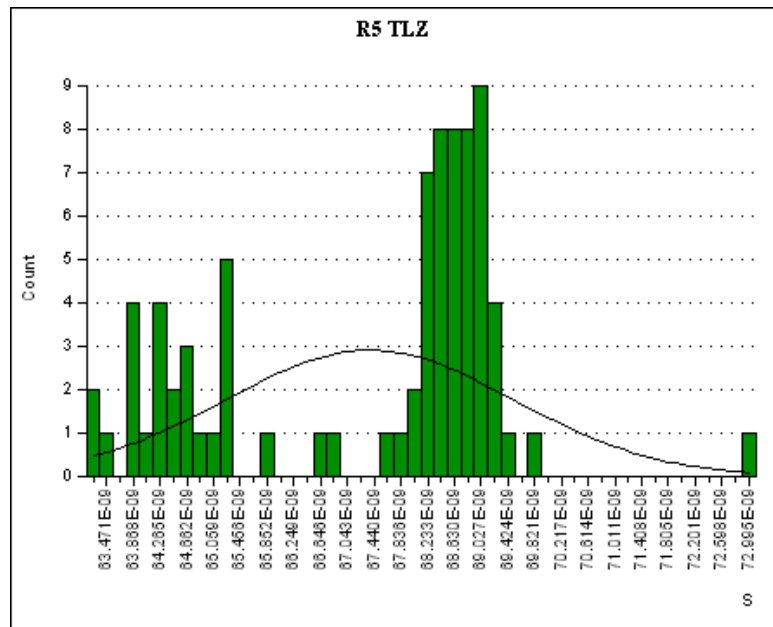
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.019, Test.Name=R5 TLZ



Statistics: (S)

Max	72.995E-09	25%	65.161E-09	SpecHigh	N/A
Mean	67.334E-09	10%	64.122E-09	SpecLow	N/A
Min	63.273E-09	N	78	PctWithinSpec	N/A
Range	9.722E-09	Cp	N/A	PctDefSpec	N/A
StdDev	2.121E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8432	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	69.125E-09	Skew	-0.4767		
75%	68.748E-09	Kurtosis	-0.6922		
Median	68.370E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

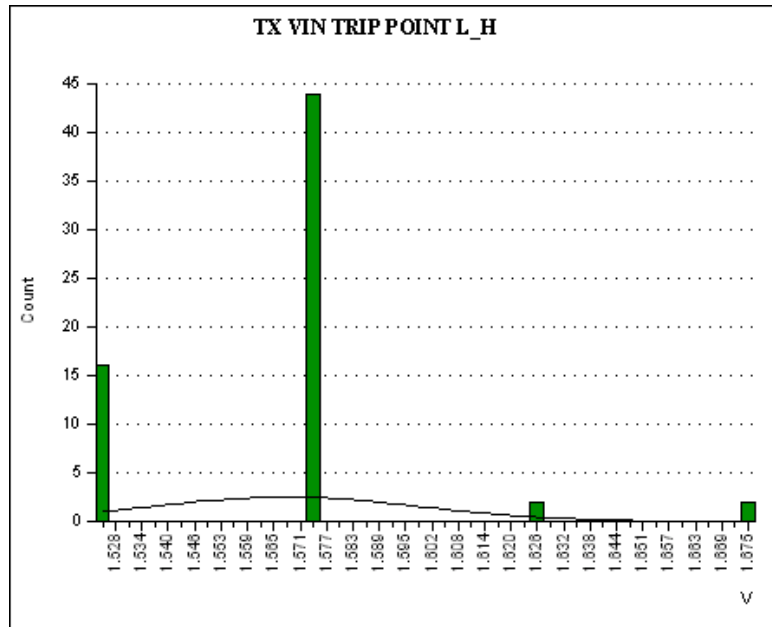
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.000, Test.Name=TX VIN TRIP POINT L_H



Statistics: (V)

Max	1.675	25%	1.550	SpecHigh	N/A
Mean	1.567	10%	1.525	SpecLow	N/A
Min	1.525	N	64	PctWithinSpec	N/A
Range	150.000E-03	Cp	N/A	PctDefSpec	N/A
StdDev	31.141E-03	Cpl	N/A	NWithinSpec	N/A
W	0.6878	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.575	Skew	0.9291		
75%	1.575	Kurtosis	3.2272		
Median	1.575				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

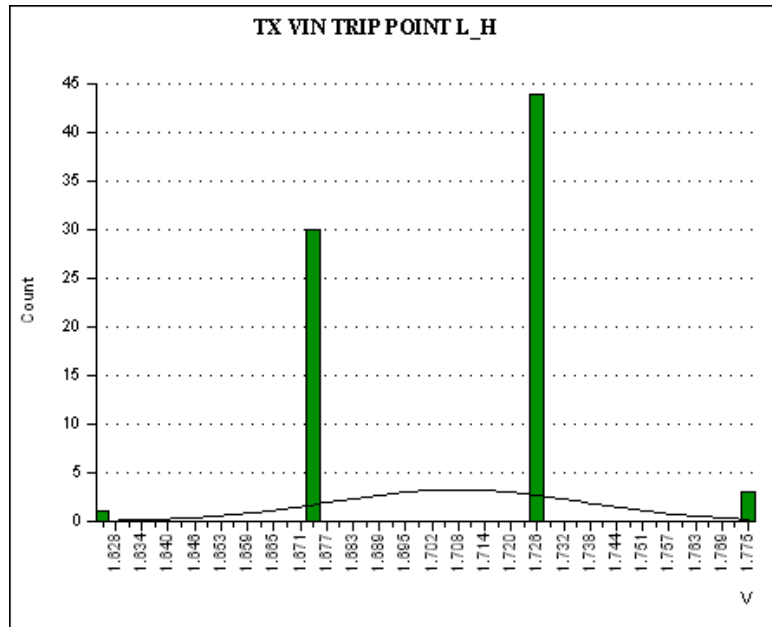
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.000, Test.Name=TX VIN TRIP POINT L_H



Statistics: (V)

Max	1.775	25%	1.675	SpecHigh	N/A
Mean	1.706	10%	1.675	SpecLow	N/A
Min	1.625	N	78	PctWithinSpec	N/A
Range	150.001E-03	Cp	N/A	PctDefSpec	N/A
StdDev	29.176E-03	Cpl	N/A	NWithinSpec	N/A
W	0.7542	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.725	Skew	-0.1173		
75%	1.725	Kurtosis	-0.3153		
Median	1.725				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

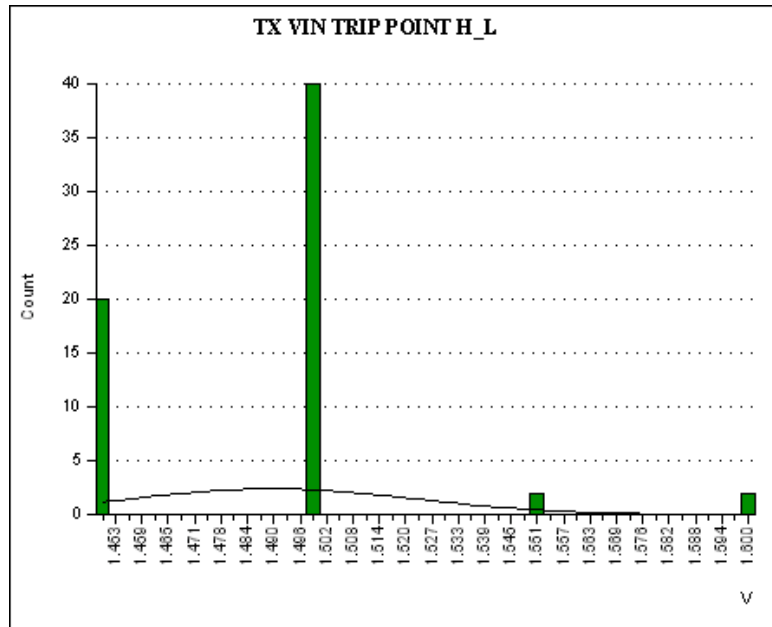
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.001, Test.Name=TX VIN TRIP POINT H_L



Statistics: (V)

Max	1.600	25%	1.450	SpecHigh	N/A
Mean	1.489	10%	1.450	SpecLow	N/A
Min	1.450	N	64	PctWithinSpec	N/A
Range	150.000E-03	Cp	N/A	PctDefSpec	N/A
StdDev	32.695E-03	Cpl	N/A	NWithinSpec	N/A
W	0.7153	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.500	Skew	0.9580		
75%	1.500	Kurtosis	2.6220		
Median	1.500				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

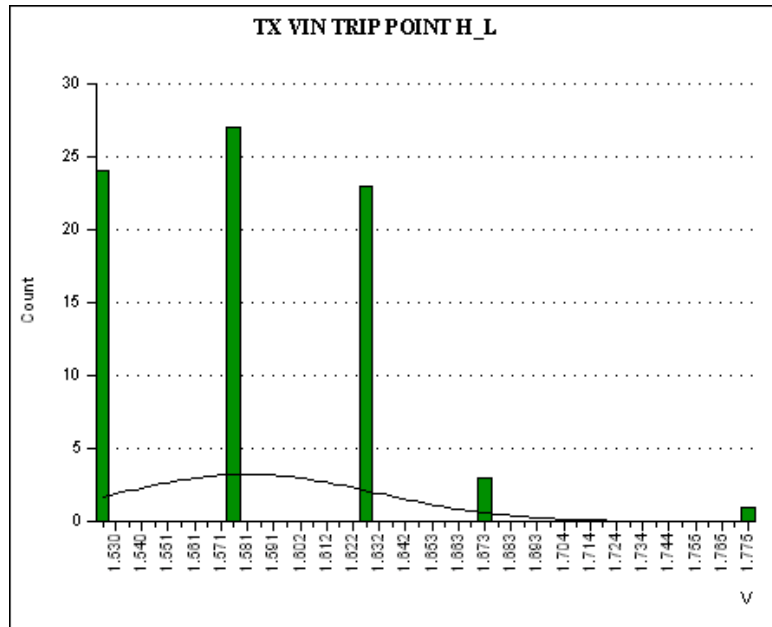
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.001, Test.Name=TX VIN TRIP POINT H_L



Statistics: (V)

Max	1.775	25%	1.525	SpecHigh	N/A
Mean	1.581	10%	1.525	SpecLow	N/A
Min	1.525	N	78	PctWithinSpec	N/A
Range	250.000E-03	Cp	N/A	PctDefSpec	N/A
StdDev	49.004E-03	Cpl	N/A	NWithinSpec	N/A
W	0.8425	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.625	Skew	0.8676		
75%	1.625	Kurtosis	1.7001		
Median	1.575				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

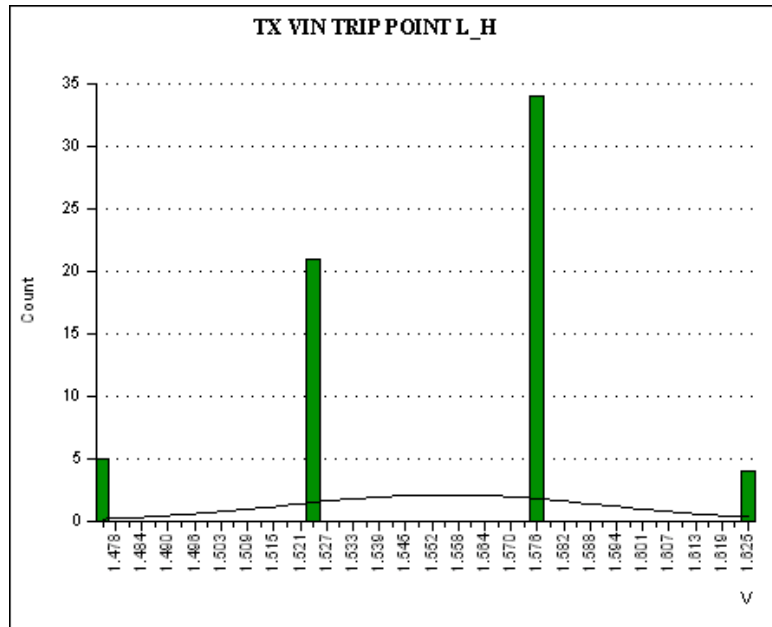
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.002, Test.Name=TX VIN TRIP POINT L_H



Statistics: (V)

Max	1.625	25%	1.525	SpecHigh	N/A
Mean	1.554	10%	1.525	SpecLow	N/A
Min	1.475	N	64	PctWithinSpec	N/A
Range	150.000E-03	Cp	N/A	PctDefSpec	N/A
StdDev	36.520E-03	Cpl	N/A	NWithinSpec	N/A
W	0.8236	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.575	Skew	-0.4061		
75%	1.575	Kurtosis	-0.0329		
Median	1.575				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

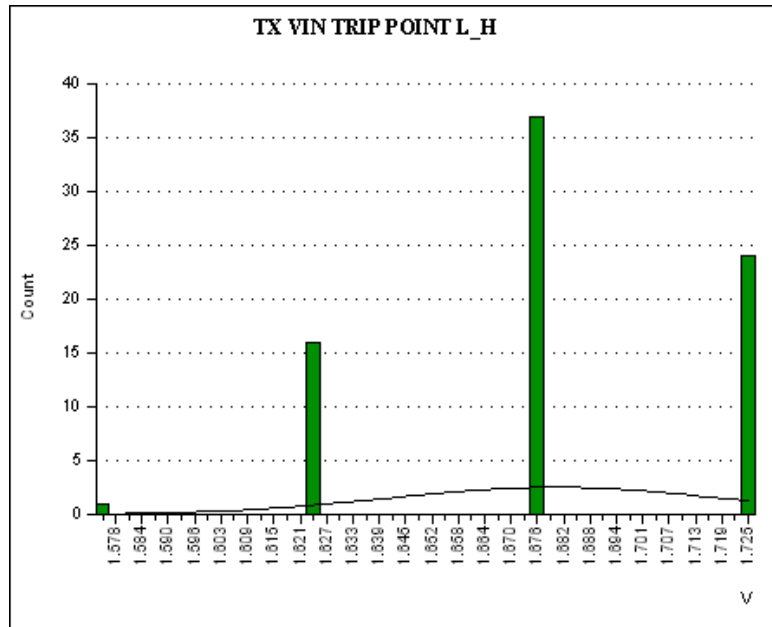
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.002, Test.Name=TX VIN TRIP POINT L_H



Statistics: (V)

Max	1.725	25%	1.675	SpecHigh	N/A
Mean	1.679	10%	1.625	SpecLow	N/A
Min	1.575	N	78	PctWithinSpec	N/A
Range	150.000E-03	Cp	N/A	PctDefSpec	N/A
StdDev	37.598E-03	Cpl	N/A	NWithinSpec	N/A
W	0.8282	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.725	Skew	-0.3161		
75%	1.725	Kurtosis	-0.5932		
Median	1.675				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

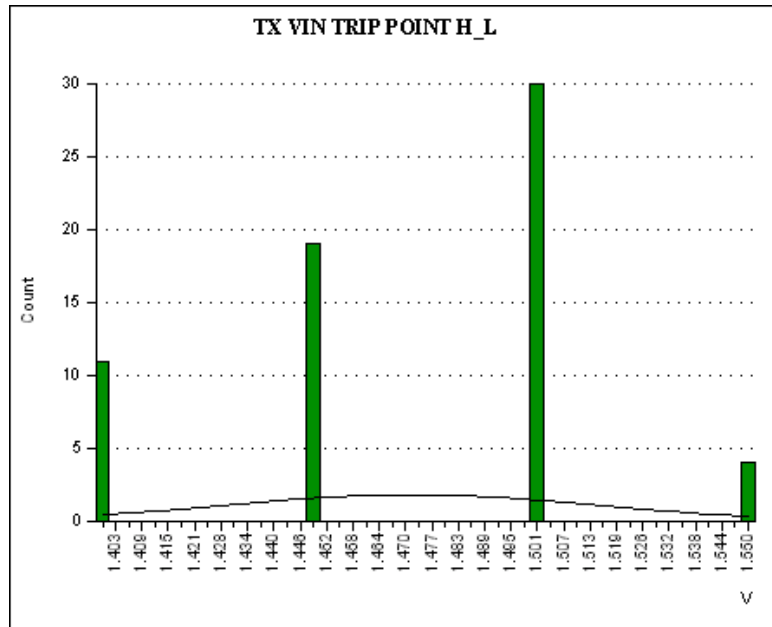
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.003, Test.Name=TX VIN TRIP POINT H_L



Statistics: (V)

Max	1.550	25%	1.450	SpecHigh	N/A
Mean	1.471	10%	1.400	SpecLow	N/A
Min	1.400	N	64	PctWithinSpec	N/A
Range	150.001E-03	Cp	N/A	PctDefSpec	N/A
StdDev	42.543E-03	Cpl	N/A	NWithinSpec	N/A
W	0.8451	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.500	Skew	-0.3067		
75%	1.500	Kurtosis	-0.6924		
Median	1.500				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

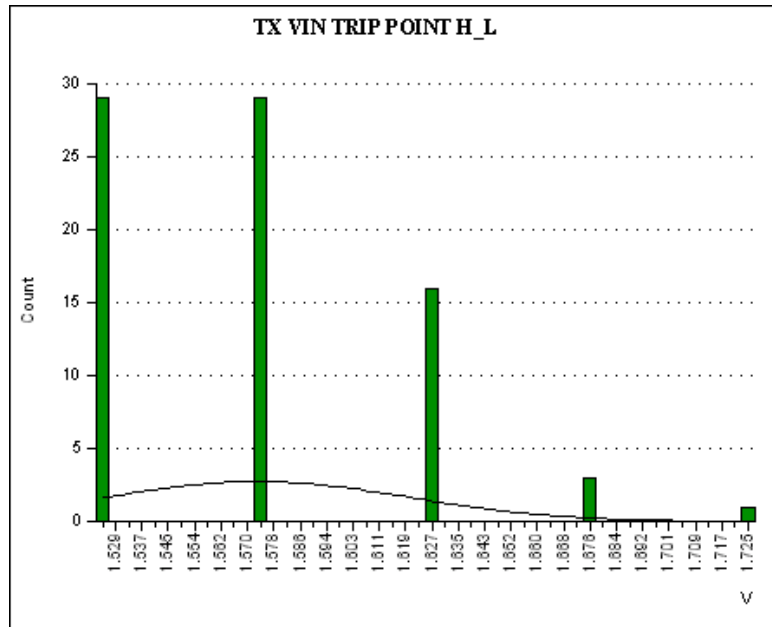
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.003, Test.Name=TX VIN TRIP POINT H_L



Statistics: (V)

Max	1.725	25%	1.525	SpecHigh	N/A
Mean	1.572	10%	1.525	SpecLow	N/A
Min	1.525	N	78	PctWithinSpe	N/A
Range	200.000E-03	Cp	N/A	c	
StdDev	46.219E-03	Cpl	N/A	PctDefSpec	N/A
W	0.8357	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	1.625	Skew	0.8122		
75%	1.625	Kurtosis	0.3951		
Median	1.575				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

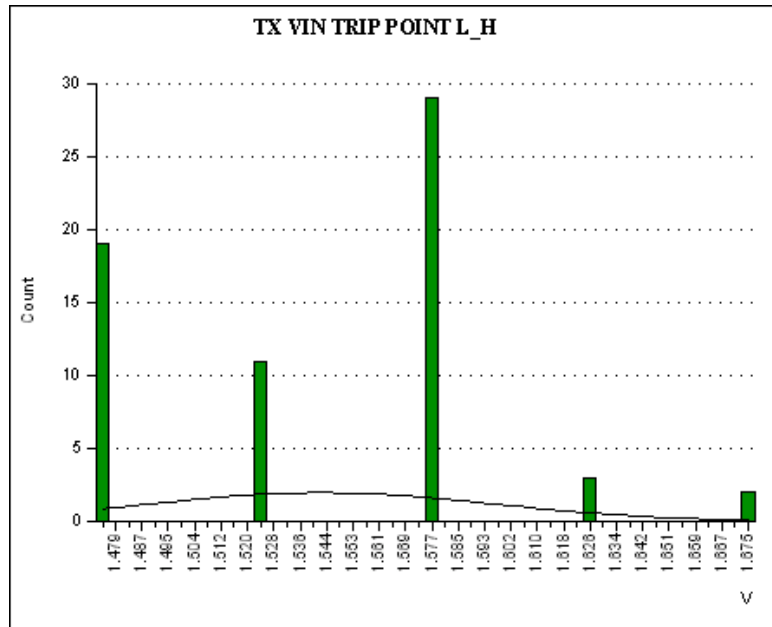
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.004, Test.Name=TX VIN TRIP POINT L_H



Statistics: (V)

Max	1.675	25%	1.475	SpecHigh	N/A
Mean	1.542	10%	1.475	SpecLow	N/A
Min	1.475	N	64	PctWithinSpec	N/A
Range	200.000E-03	Cp	N/A	PctDefSpec	N/A
StdDev	52.869E-03	Cpl	N/A	NWithinSpec	N/A
W	0.8397	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.575	Skew	0.1769		
75%	1.575	Kurtosis	-0.4999		
Median	1.575				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

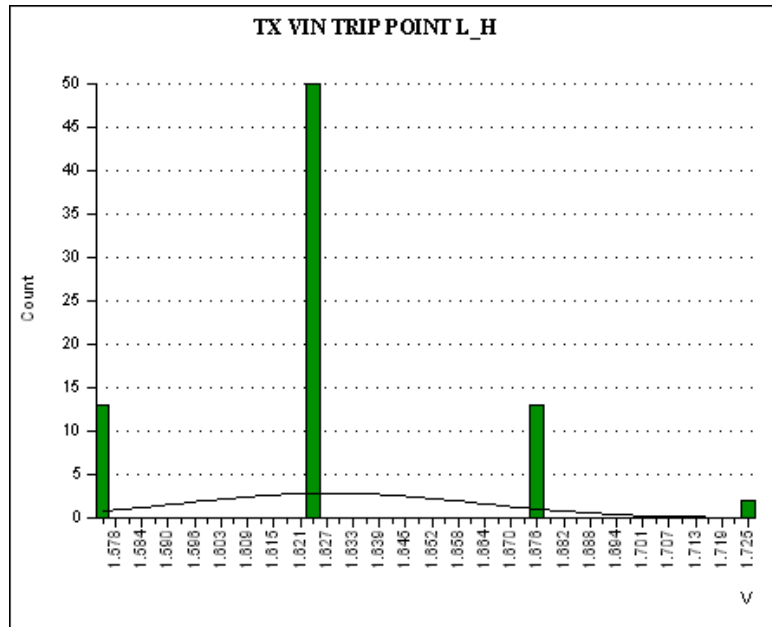
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.004, Test.Name=TX VIN TRIP POINT L_H



Statistics: (V)

Max	1.725	25%	1.625	SpecHigh	N/A
Mean	1.628	10%	1.575	SpecLow	N/A
Min	1.575	N	78	PctWithinSpec	N/A
Range	150.000E-03	Cp	N/A	PctDefSpec	N/A
StdDev	33.124E-03	Cpl	N/A	NWithinSpec	N/A
W	0.7863	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.675	Skew	0.4947		
75%	1.625	Kurtosis	0.9066		
Median	1.625				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

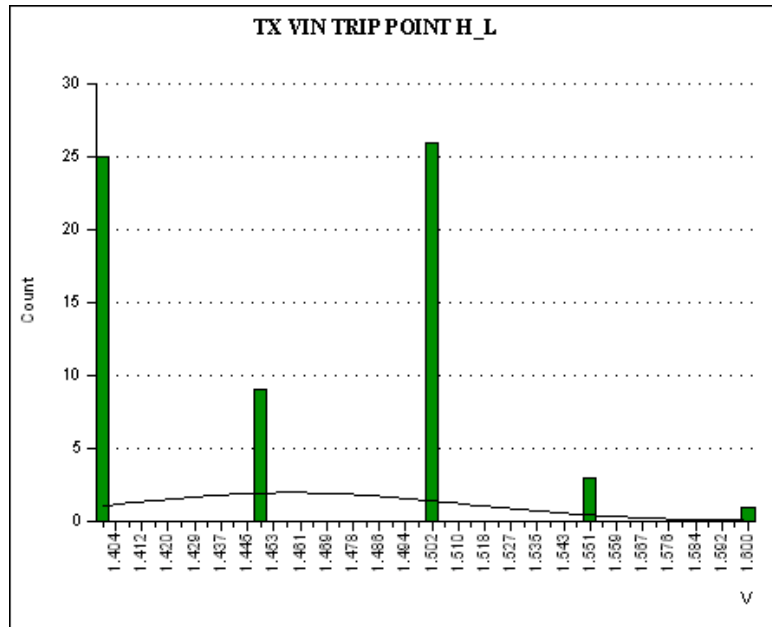
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.005, Test.Name=TX VIN TRIP POINT H_L



Statistics: (V)

Max	1.600	25%	1.400	SpecHigh	N/A
Mean	1.458	10%	1.400	SpecLow	N/A
Min	1.400	N	64	PctWithinSpec	N/A
Range	200.000E-03	Cp	N/A	c	
StdDev	52.869E-03	Cpl	N/A	PctDefSpec	N/A
W	0.8116	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	1.500	Skew	0.2597		
75%	1.500	Kurtosis	-0.9425		
Median	1.450				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

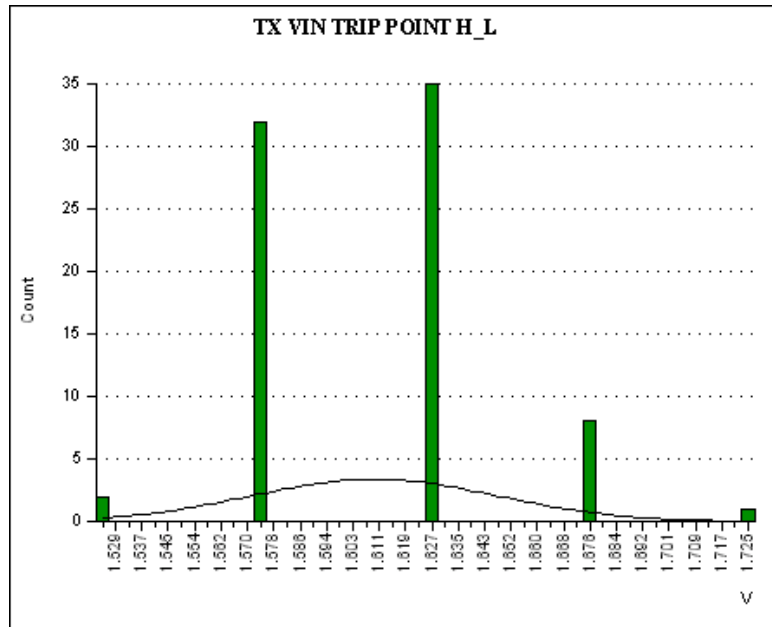
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.005, Test.Name=TX VIN TRIP POINT H_L



Statistics: (V)

Max	1.725	25%	1.575	SpecHigh	N/A
Mean	1.608	10%	1.575	SpecLow	N/A
Min	1.525	N	78	PctWithinSpec	N/A
Range	200.000E-03	Cp	N/A	PctDefSpec	N/A
StdDev	37.509E-03	Cpl	N/A	NWithinSpec	N/A
W	0.8389	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.675	Skew	0.4490		
75%	1.625	Kurtosis	0.2978		
Median	1.625				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

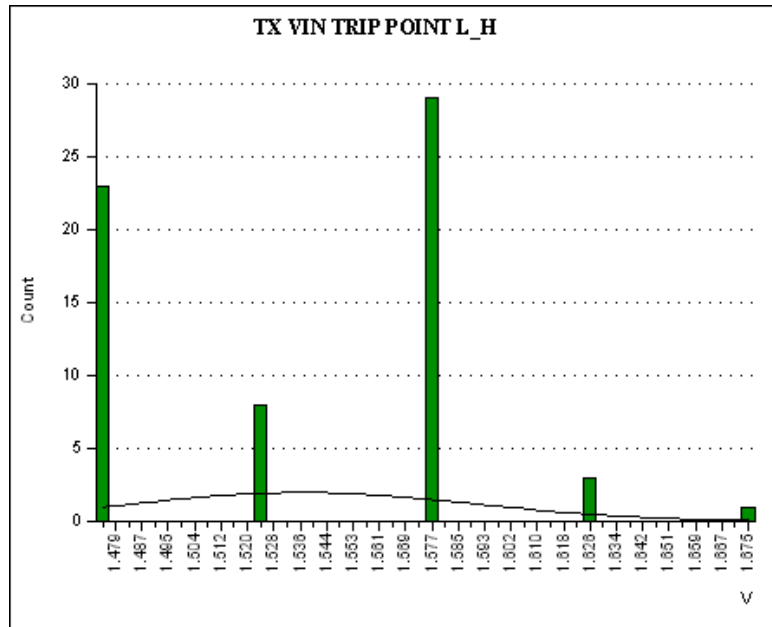
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.006, Test.Name=TX VIN TRIP POINT L_H



Statistics: (V)

Max	1.675	25%	1.475	SpecHigh	N/A
Mean	1.537	10%	1.475	SpecLow	N/A
Min	1.475	N	64	PctWithinSpec	N/A
Range	200.000E-03	Cp	N/A	PctDefSpec	N/A
StdDev	52.510E-03	Cpl	N/A	NWithinSpec	N/A
W	0.8071	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.575	Skew	0.1035		
75%	1.575	Kurtosis	-0.9805		
Median	1.575				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

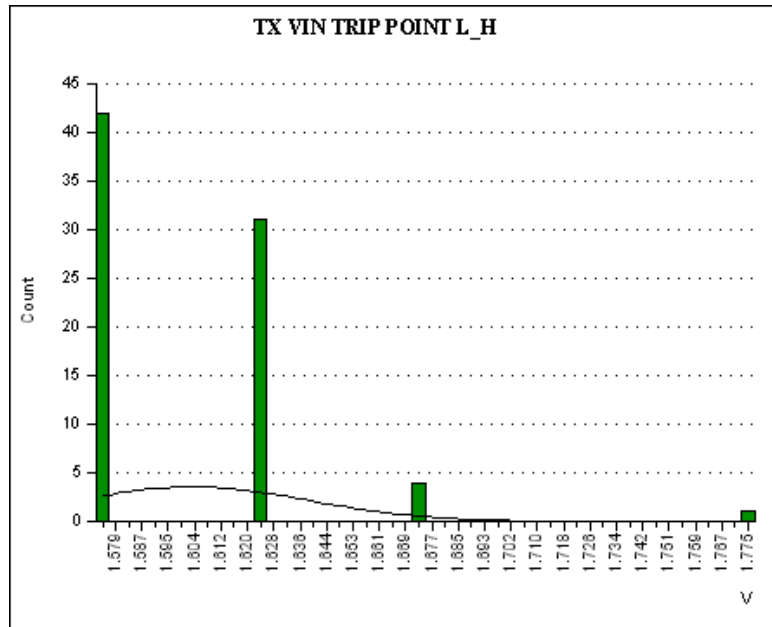
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.006, Test.Name=TX VIN TRIP POINT L_H



Statistics: (V)

Max	1.775	25%	1.575	SpecHigh	N/A
Mean	1.603	10%	1.575	SpecLow	N/A
Min	1.575	N	78	PctWithinSpec	N/A
Range	200.000E-03	Cp	N/A	PctDefSpec	N/A
StdDev	35.718E-03	Cpl	N/A	NWithinSpec	N/A
W	0.6921	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.625	Skew	1.7895		
75%	1.625	Kurtosis	5.7325		
Median	1.575				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

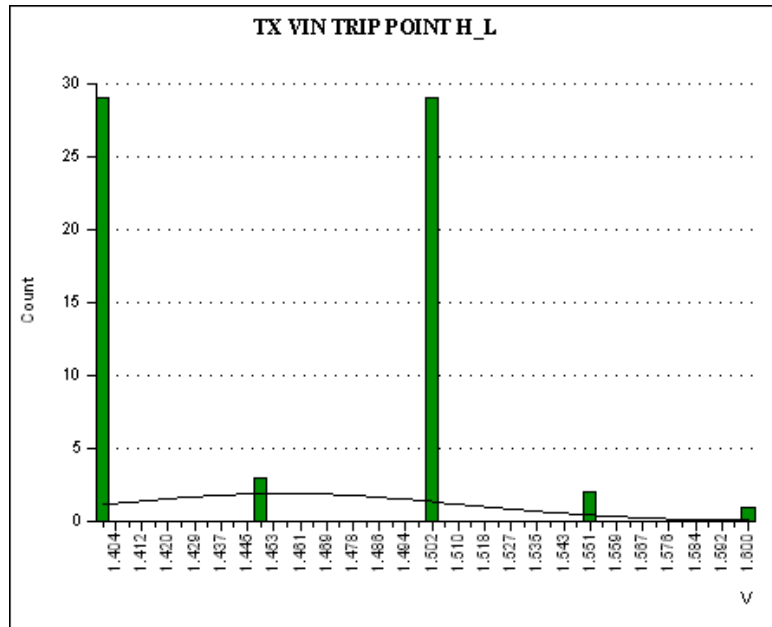
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.007, Test.Name=TX VIN TRIP POINT H_L



Statistics: (V)

Max	1.600	25%	1.400	SpecHigh	N/A
Mean	1.455	10%	1.400	SpecLow	N/A
Min	1.400	N	64	PctWithinSpec	N/A
Range	200.000E-03	Cp	N/A	PctDefSpec	N/A
StdDev	54.275E-03	Cpl	N/A	NWithinSpec	N/A
W	0.7518	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.500	Skew	0.2377		
75%	1.500	Kurtosis	-1.1673		
Median	1.475				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C5C: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5H: N/A	SYN1035	SP213	_	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECHO 1.AT	-	0
24634C5R: N/A	SYN1035	SP213	_	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECHO 1.AT	-	0

Data: Raw Data

Stat limits applied

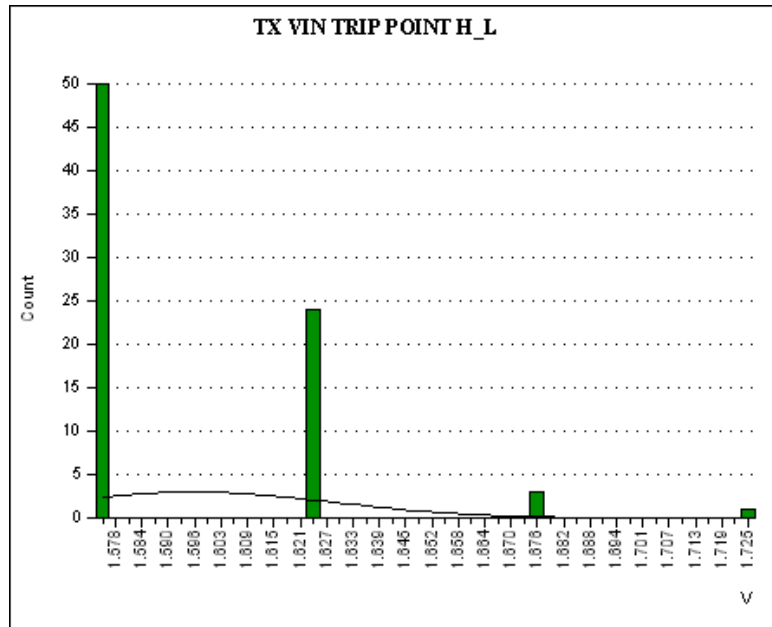
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.007, Test.Name=TX VIN TRIP POINT H_L



Statistics: (V)

Max	1.725	25%	1.575	SpecHigh	N/A
Mean	1.596	10%	1.575	SpecLow	N/A
Min	1.575	N	78	PctWithinSpec	N/A
Range	150.000E-03	Cp	N/A	PctDefSpec	N/A
StdDev	31.745E-03	Cpl	N/A	NWithinSpec	N/A
W	0.6618	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.625	Skew	1.5467		
75%	1.625	Kurtosis	2.6606		
Median	1.575				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L25C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A T	-	0
213L25H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0
213L25R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A T	-	0

Data: Raw Data

Stat limits applied

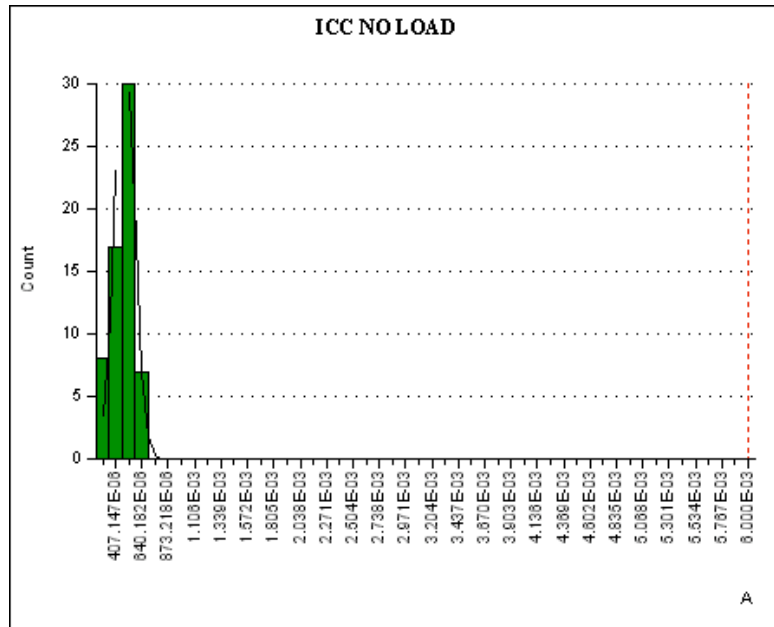
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=1.000, Test.Name=ICC NO LOAD



Statistics: (A)

Max	668.939E-06	25%	430.604E-06	SpecHigh	6.000E-03
Mean	478.247E-06	10%	336.129E-06	SpecLow	N/A
Min	290.629E-06	N	62	PctWithinSpec	100.00
Range	378.310E-06	Cp	N/A	PctDefSpec	0
StdDev	88.314E-06	Cpl	N/A	NWithinSpec	62
W	0.9725	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.1782	Cpk	>4.0000		
90%	586.833E-06	Skew	-0.3236		
75%	532.047E-06	Kurtosis	-0.0855		
Median	492.548E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

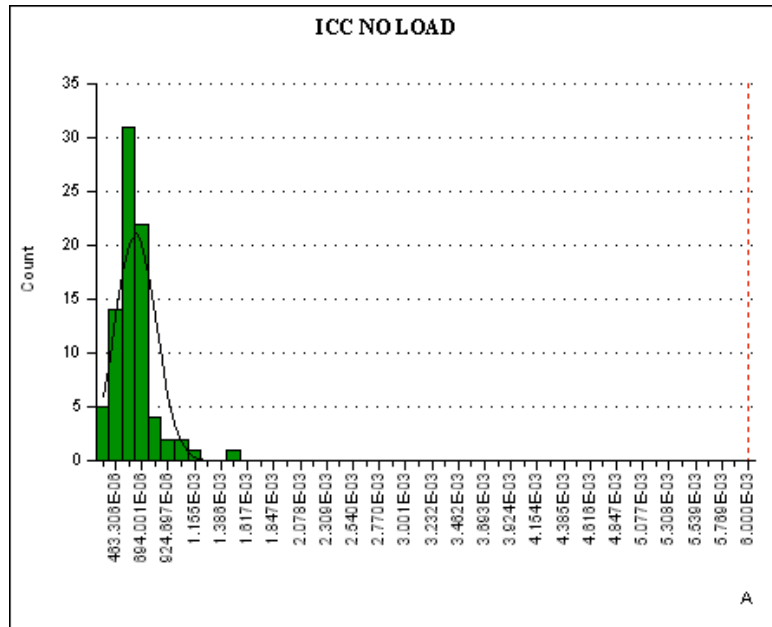
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=1.000, Test.Name=ICC NO LOAD



Statistics: (A)

Max	1.470E-03	25%	534.256E-06	SpecHigh	6.000E-03
Mean	629.960E-06	10%	445.926E-06	SpecLow	N/A
Min	347.958E-06	N	82	PctWithinSpec	100.00
Range	1.122E-03	Cp	N/A	c	
StdDev	177.976E-06	Cpl	N/A	PctDefSpec	0
W	0.8473	Cpu	>4.0000	NWithinSpec	82
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	824.619E-06	Skew	1.9732		
75%	677.022E-06	Kurtosis	6.5734		
Median	607.581E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

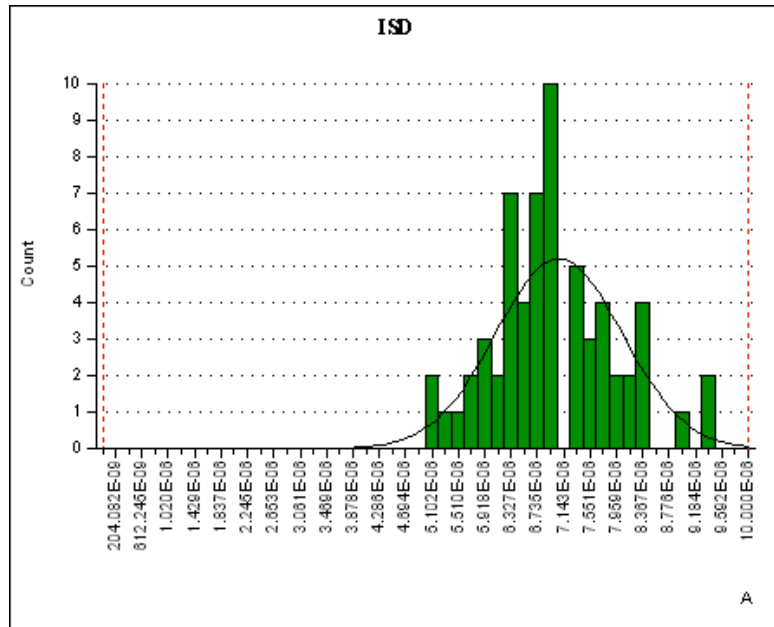
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=1.002, Test.Name=ISD



Statistics: (A)

Max	9.451E-06	25%	6.380E-06	SpecHigh	10.000E-06
Mean	6.993E-06	10%	5.891E-06	SpecLow	0
Min	5.072E-06	N	62	PctWithinSpec	100.00
Range	4.379E-06	Cp	1.7207	c	
StdDev	968.602E-09	Cpl	2.4064	PctDefSpec	0
W	0.9777	Cpu	1.0350	NWithinSpec	62
WpValue	0.3191	Cpk	1.0350	NOutsideSpec	0
90%	8.342E-06	Skew	0.4394		
75%	7.622E-06	Kurtosis	0.1958		
Median	6.932E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

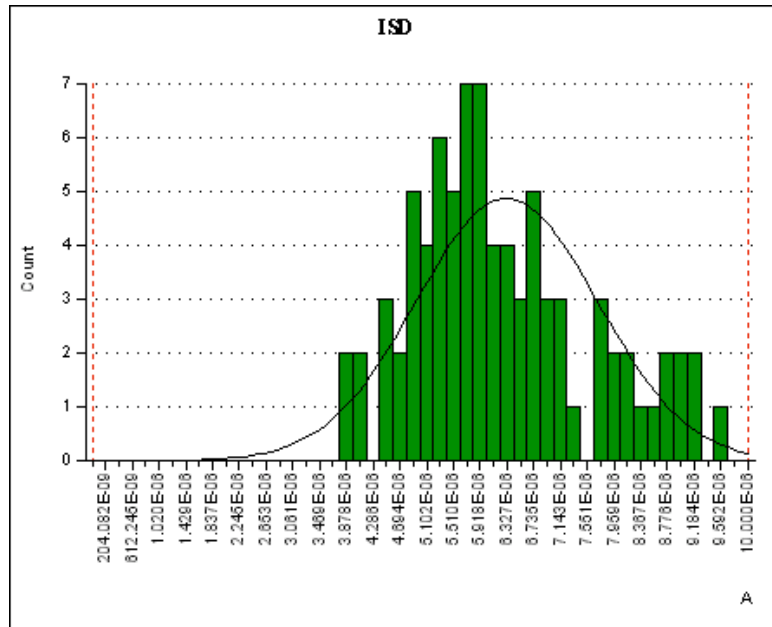
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=1.002, Test.Name=ISD



Statistics: (A)

Max	9.646E-06	25%	5.320E-06	SpecHigh	10.000E-06
Mean	6.248E-06	10%	4.789E-06	SpecLow	0
Min	3.813E-06	N	82	PctWithinSpec	100.00
Range	5.833E-06	Cp	1.2177	PctDefSpec	0
StdDev	1.369E-06	Cpl	1.5217	NWithinSpec	82
W	0.9589	Cpu	0.9137	NOutsideSpec	0
WpValue	0.0102	Cpk	0.9137		
90%	8.374E-06	Skew	0.5752		
75%	6.943E-06	Kurtosis	-0.2938		
Median	5.958E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

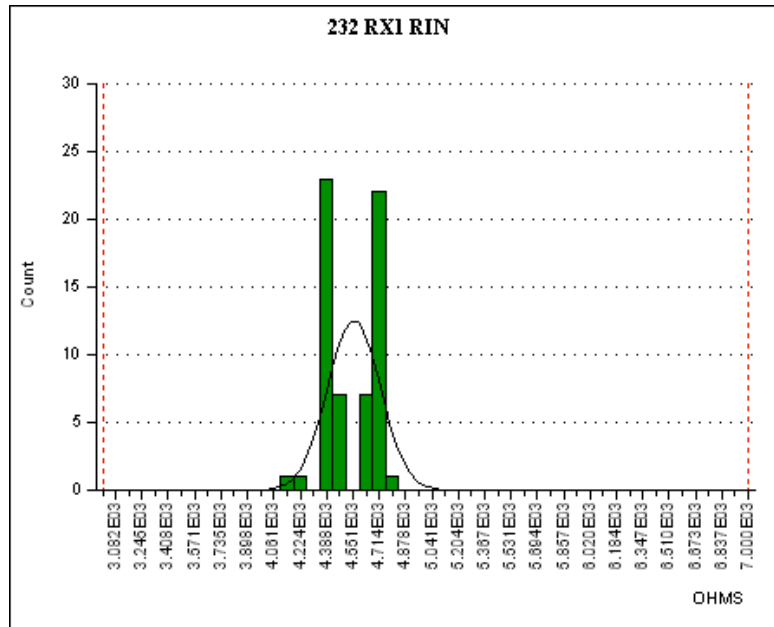
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=2.000, Test.Name=232 RX1 RIN



Statistics: (OHMS)

Max	4.760E03	25%	4.401E03	SpecHigh	7.000E03
Mean	4.539E03	10%	4.375E03	SpecLow	3.000E03
Min	4.147E03	N	62	PctWithinSpec	100.00
Range	613.176	Cp	>4.0000	c	
StdDev	160.445	Cpl	3.1973	PctDefSpec	0
W	0.8589	Cpu	>4.0000	NWithinSpec	62
WpValue	0.0000	Cpk	3.1973	NOutsideSpec	0
90%	4.722E03	Skew	-0.2142		
75%	4.695E03	Kurtosis	-1.1830		
Median	4.467E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

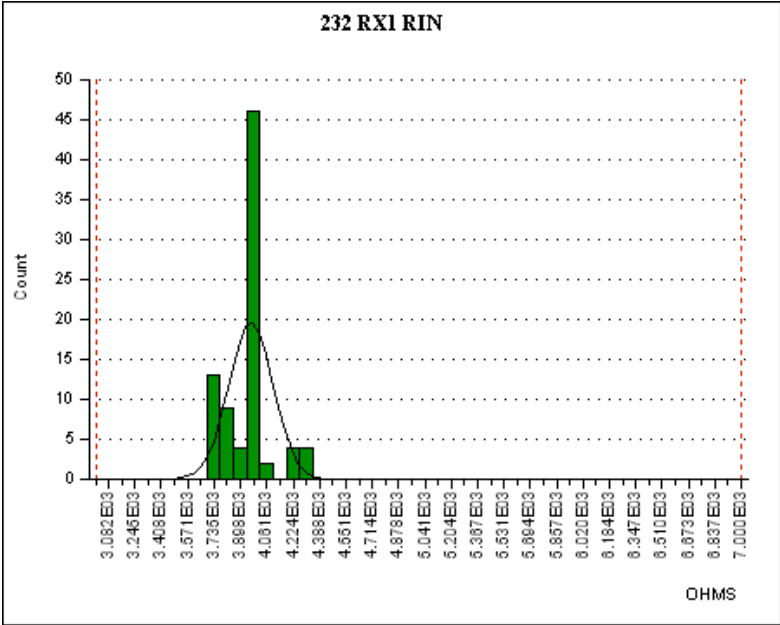
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=2.000, Test.Name=232 RX1 RIN



Statistics: (OHMS)

Max	4.284E03	25%	3.850E03	SpecHigh	7.000E03
Mean	3.950E03	10%	3.754E03	SpecLow	3.000E03
Min	3.723E03	N	82	PctWithinSpec	100.00
Range	561.167	Cp	>4.0000	PctDefSpec	0
StdDev	136.537	Cpl	2.3189	NWithinSpec	82
W	0.8821	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	2.3189		
90%	4.048E03	Skew	0.5707		
75%	3.992E03	Kurtosis	0.6451		
Median	3.962E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

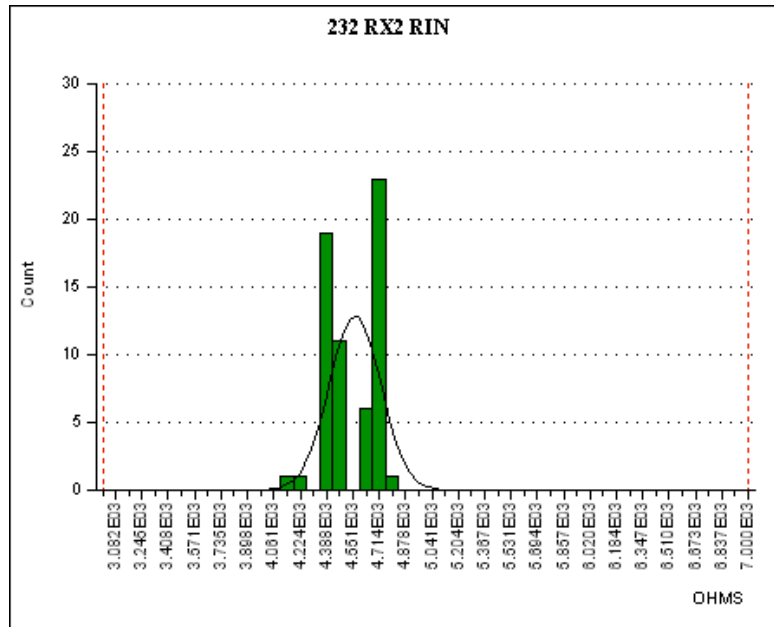
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=2.001, Test.Name=232 RX2 RIN



Statistics: (OHMS)

Max	4.760E03	25%	4.408E03	SpecHigh	7.000E03
Mean	4.546E03	10%	4.391E03	SpecLow	3.000E03
Min	4.161E03	N	62	PctWithinSpec	100.00
Range	598.852	Cp	>4.0000	c	
StdDev	156.910	Cpl	3.2839	PctDefSpec	0
W	0.8424	Cpu	>4.0000	NWithinSpec	62
WpValue	0.0000	Cpk	3.2839	NOutsideSpec	0
90%	4.718E03	Skew	-0.2229		
75%	4.695E03	Kurtosis	-1.1794		
Median	4.469E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

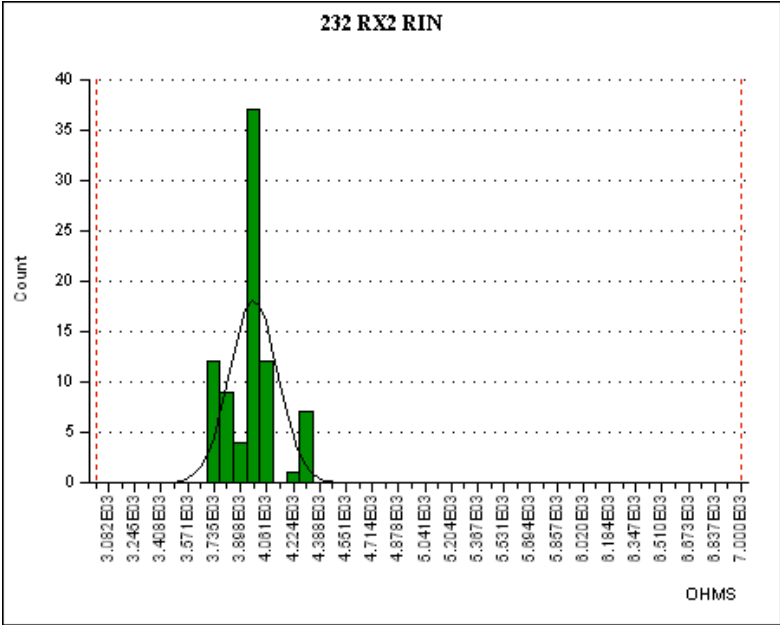
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=2.001, Test.Name=232 RX2 RIN



Statistics: (OHMS)

Max	4.313E03	25%	3.843E03	SpecHigh	7.000E03
Mean	3.966E03	10%	3.754E03	SpecLow	3.000E03
Min	3.719E03	N	82	PctWithinSpec	100.00
Range	593.257	Cp	>4.0000	PctDefSpec	0
StdDev	147.430	Cpl	2.1835	NWithinSpec	82
W	0.8940	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	2.1835		
90%	4.064E03	Skew	0.3875		
75%	4.019E03	Kurtosis	0.3403		
Median	3.988E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

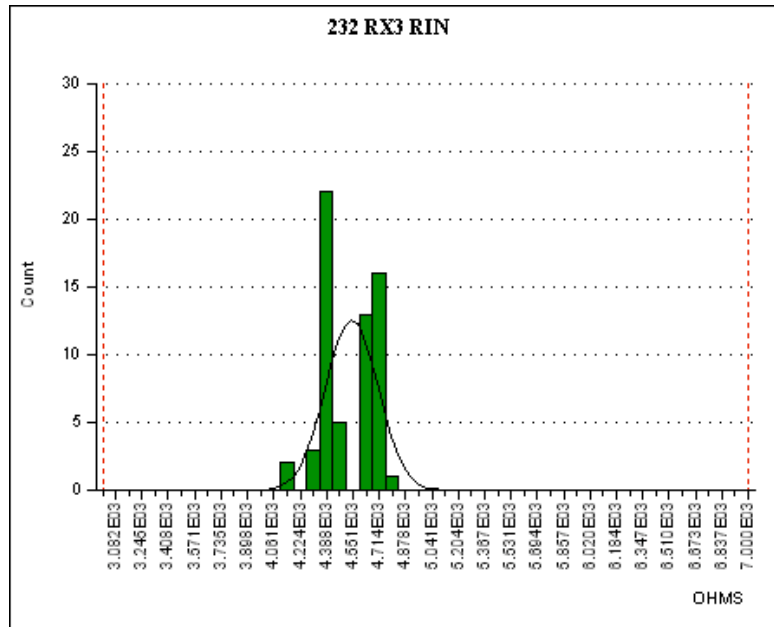
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=2.002, Test.Name=232 RX3 RIN



Statistics: (OHMS)

Max	4.761E03	25%	4.389E03	SpecHigh	7.000E03
Mean	4.526E03	10%	4.373E03	SpecLow	3.000E03
Min	4.148E03	N	62	PctWithinSpec	100.00
Range	613.344	Cp	>4.0000	c	
StdDev	160.148	Cpl	3.1752	PctDefSpec	0
W	0.8651	Cpu	>4.0000	NWithinSpec	62
WpValue	0.0000	Cpk	3.1752	NOutsideSpec	0
90%	4.703E03	Skew	-0.2139		
75%	4.678E03	Kurtosis	-1.1773		
Median	4.463E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

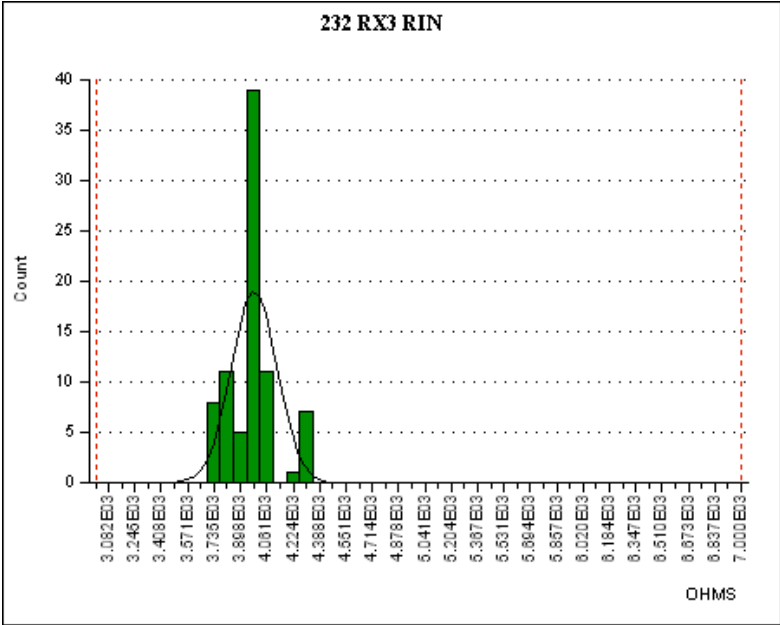
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=2.002, Test.Name=232 RX3 RIN



Statistics: (OHMS)

Max	4.322E03	25%	3.880E03	SpecHigh	7.000E03
Mean	3.970E03	10%	3.777E03	SpecLow	3.000E03
Min	3.727E03	N	82	PctWithinSpec	100.00
Range	595.004	Cp	>4.0000	PctDefSpec	0
StdDev	140.190	Cpl	2.3059	NWithinSpec	82
W	0.8955	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	2.3059		
90%	4.062E03	Skew	0.5123		
75%	4.016E03	Kurtosis	0.5812		
Median	3.983E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

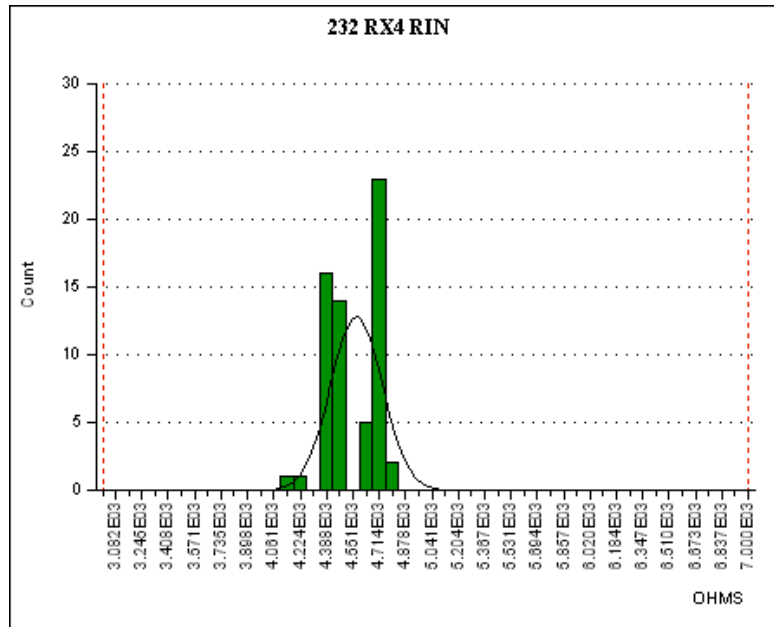
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=2.003, Test.Name=232 RX4 RIN



Statistics: (OHMS)

Max	4.775E03	25%	4.420E03	SpecHigh	7.000E03
Mean	4.555E03	10%	4.396E03	SpecLow	3.000E03
Min	4.175E03	N	62	PctWithinSpec	100.00
Range	599.828	Cp	>4.0000	c	
StdDev	156.718	Cpl	3.3069	PctDefSpec	0
W	0.8599	Cpu	>4.0000	NWithinSpec	62
WpValue	0.0000	Cpk	3.3069	NOutsideSpec	0
90%	4.730E03	Skew	-0.2273		
75%	4.704E03	Kurtosis	-1.1398		
Median	4.484E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

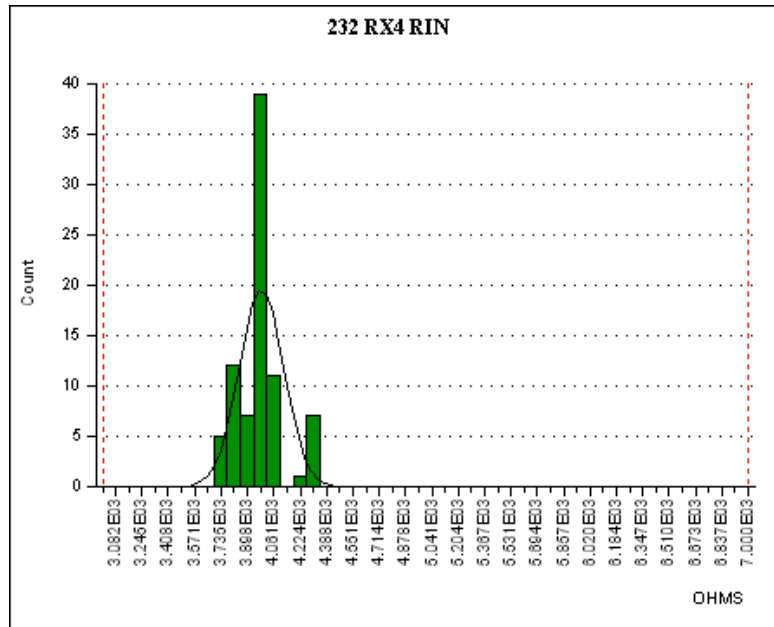
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=2.003, Test.Name=232 RX4 RIN



Statistics: (OHMS)

Max	4.318E03	25%	3.888E03	SpecHigh	7.000E03
Mean	3.971E03	10%	3.781E03	SpecLow	3.000E03
Min	3.728E03	N	82	PctWithinSpec	100.00
Range	589.628	Cp	>4.0000	PctDefSpec	0
StdDev	136.268	Cpl	2.3759	NWithinSpec	82
W	0.8882	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	2.3759		
90%	4.049E03	Skew	0.6042		
75%	4.016E03	Kurtosis	0.7846		
Median	3.984E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

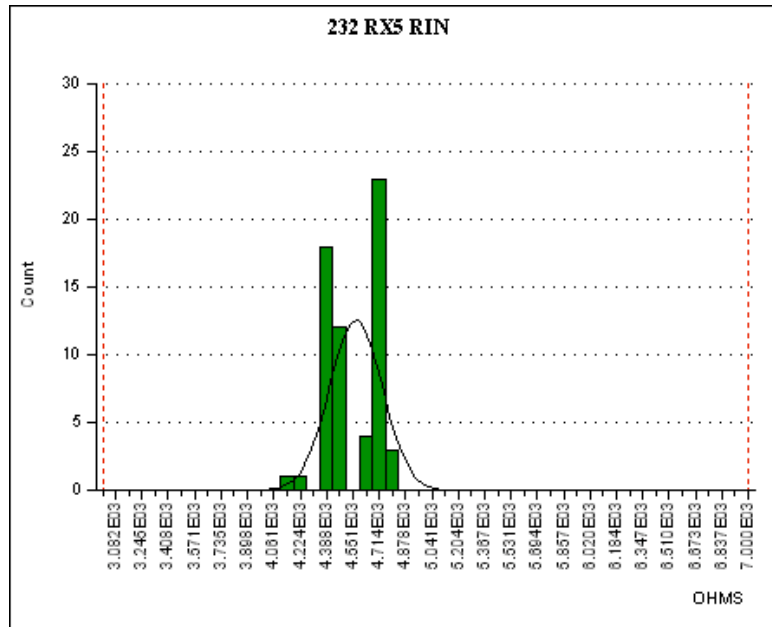
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=2.004, Test.Name=232 RX5 RIN



Statistics: (OHMS)

Max	4.771E03	25%	4.413E03	SpecHigh	7.000E03
Mean	4.552E03	10%	4.388E03	SpecLow	3.000E03
Min	4.160E03	N	62	PctWithinSpec	100.00
Range	610.730	Cp	>4.0000	c	
StdDev	160.932	Cpl	3.2137	PctDefSpec	0
W	0.8574	Cpu	>4.0000	NWithinSpec	62
WpValue	0.0000	Cpk	3.2137	NOutsideSpec	0
90%	4.726E03	Skew	-0.2351		
75%	4.703E03	Kurtosis	-1.1287		
Median	4.478E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

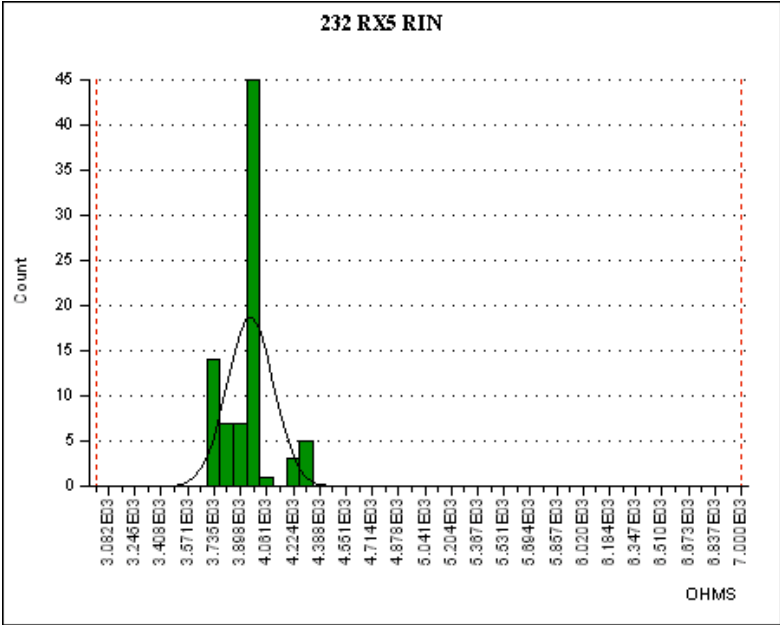
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=2.004, Test.Name=232 RX5 RIN



Statistics: (OHMS)

Max	4.299E03	25%	3.845E03	SpecHigh	7.000E03
Mean	3.946E03	10%	3.739E03	SpecLow	3.000E03
Min	3.705E03	N	82	PctWithinSpec	100.00
Range	593.424	Cp	>4.0000	c	
StdDev	142.438	Cpl	2.2143	PctDefSpec	0
W	0.8783	Cpu	>4.0000	NWithinSpec	82
WpValue	0.0000	Cpk	2.2143	NOutsideSpec	0
90%	4.025E03	Skew	0.6151		
75%	3.993E03	Kurtosis	0.7831		
Median	3.963E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

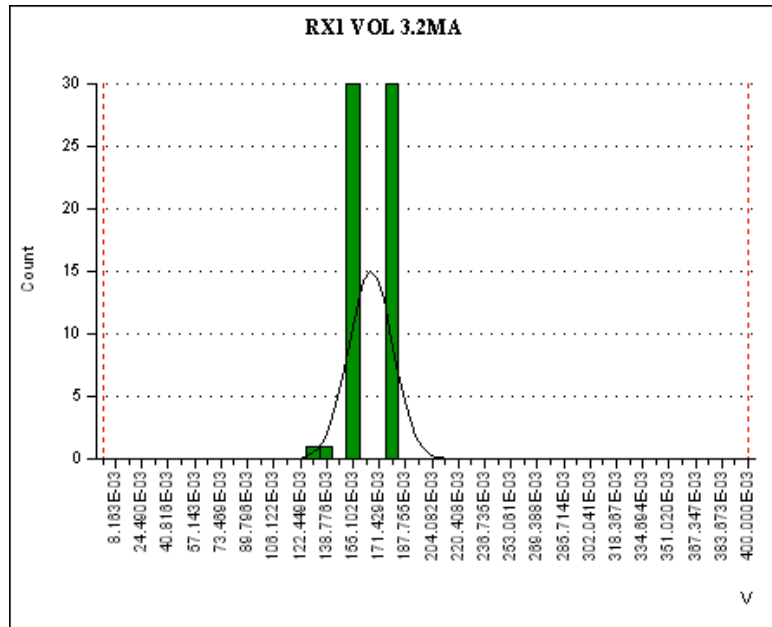
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=3.000, Test.Name=RX1 VOL 3.2MA



Statistics: (V)

Max	180.148E-03	25%	152.945E-03	SpecHigh	400.000E-03
Mean	164.233E-03	10%	151.878E-03	SpecLow	0
Min	134.679E-03	N	62	PctWithinSpec	100.00
Range	45.469E-03	Cp	>4.0000	c	
StdDev	13.430E-03	Cpl	>4.0000	PctDefSpec	0
W	0.7572	Cpu	>4.0000	NWithinSpec	62
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	178.356E-03	Skew	-0.1566		
75%	177.707E-03	Kurtosis	-1.5061		
Median	154.108E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

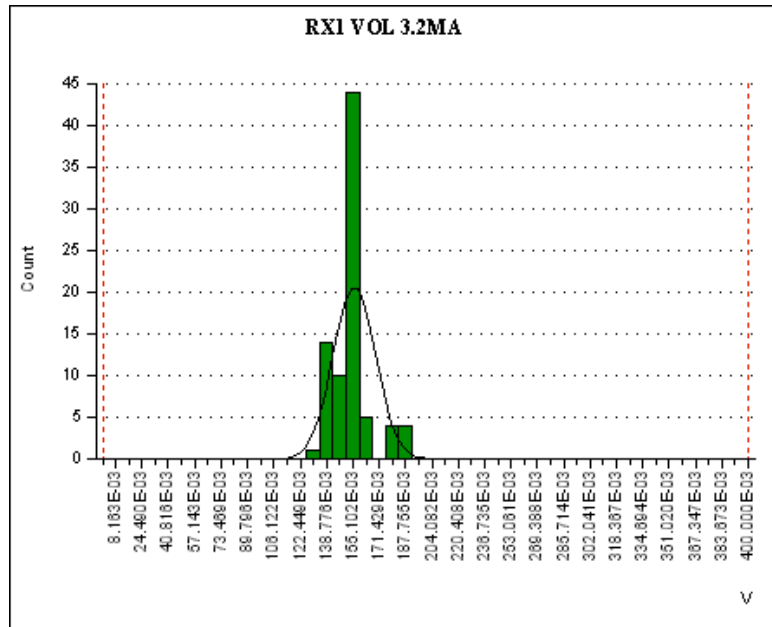
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.000, Test.Name=RX1 VOL 3.2MA



Statistics: (V)

Max	188.763E-03	25%	146.267E-03	SpecHigh	400.000E-03
Mean	154.197E-03	10%	136.970E-03	SpecLow	0
Min	131.748E-03	N	82	PctWithinSpec	100.00
Range	57.014E-03	Cp	>4.0000	c	
StdDev	12.900E-03	Cpl	3.9844	PctDefSpec	0
W	0.8709	Cpu	>4.0000	NWithinSpec	82
WpValue	0.0000	Cpk	3.9844	NOutsideSpec	0
90%	161.360E-03	Skew	0.8766		
75%	158.121E-03	Kurtosis	1.3018		
Median	155.168E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

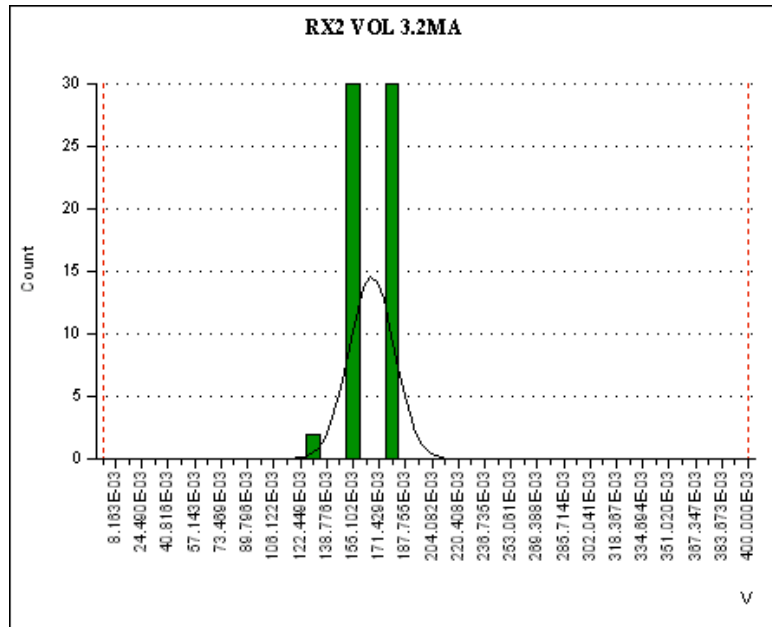
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.001, Test.Name=RX2 VOL 3.2MA



Statistics: (V)

Max	181.025E-03	25%	152.983E-03	SpecHigh	400.000E-03
Mean	164.773E-03	10%	152.221E-03	SpecLow	0
Min	133.916E-03	N	62	PctWithinSpec	100.00
Range	47.108E-03	Cp	>4.0000	c	
StdDev	13.811E-03	Cpl	3.9768	PctDefSpec	0
W	0.7671	Cpu	>4.0000	NWithinSpec	62
WpValue	0.0000	Cpk	3.9768	NOutsideSpec	0
90%	179.233E-03	Skew	-0.1734		
75%	178.279E-03	Kurtosis	-1.4479		
Median	154.794E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

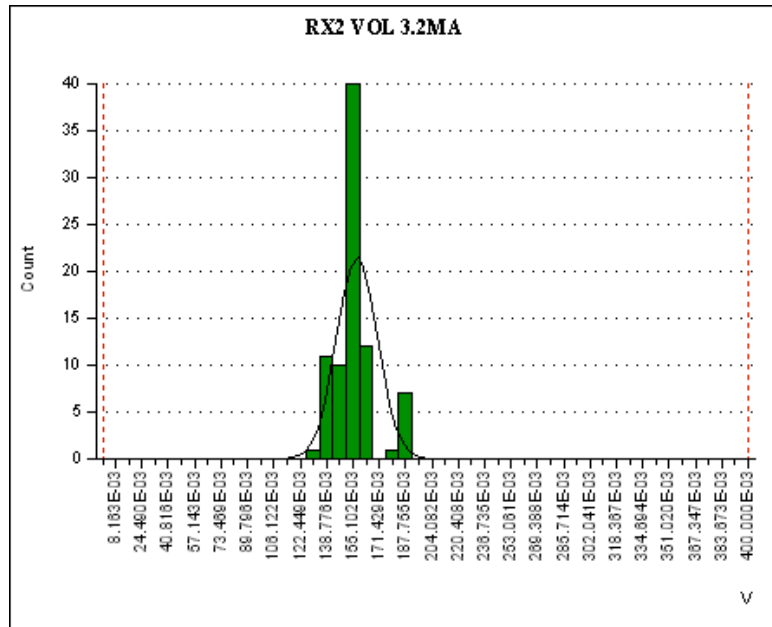
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.001, Test.Name=RX2 VOL 3.2MA



Statistics: (V)

Max	189.106E-03	25%	148.517E-03	SpecHigh	400.000E-03
Mean	155.768E-03	10%	139.826E-03	SpecLow	0
Min	134.568E-03	N	82	PctWithinSpec	100.00
Range	54.538E-03	Cp	>4.0000	c	
StdDev	12.379E-03	Cpl	>4.0000	PctDefSpec	0
W	0.8641	Cpu	>4.0000	NWithinSpec	82
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	163.609E-03	Skew	0.9156		
75%	158.921E-03	Kurtosis	1.4354		
Median	156.253E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

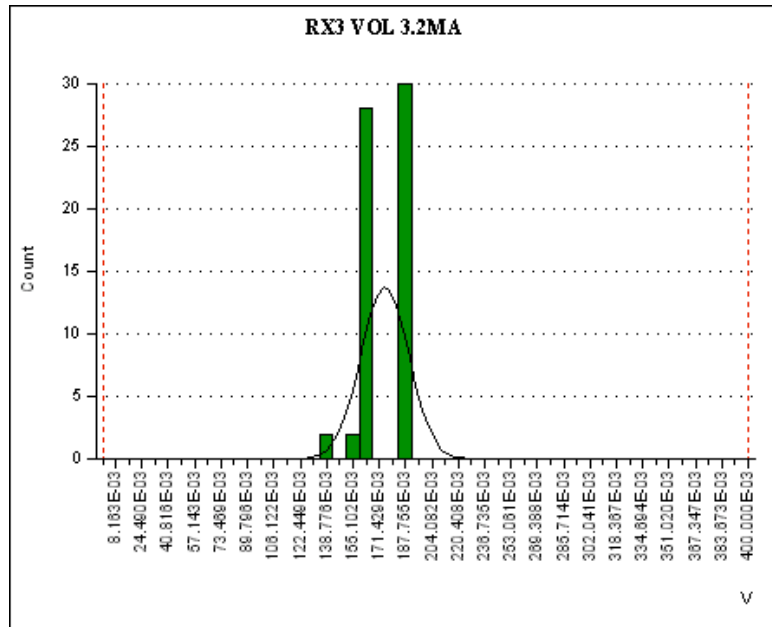
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.002, Test.Name=RX3 VOL 3.2MA



Statistics: (V)

Max	189.561E-03	25%	160.302E-03	SpecHigh	400.000E-03
Mean	172.746E-03	10%	159.730E-03	SpecLow	0
Min	140.205E-03	N	62	PctWithinSpec	100.00
Range	49.356E-03	Cp	>4.0000	c	
StdDev	14.631E-03	Cpl	3.9358	PctDefSpec	0
W	0.7624	Cpu	>4.0000	NWithinSpec	62
WpValue	0.0000	Cpk	3.9358	NOutsideSpec	0
90%	188.076E-03	Skew	-0.1708		
75%	187.428E-03	Kurtosis	-1.4552		
Median	161.960E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

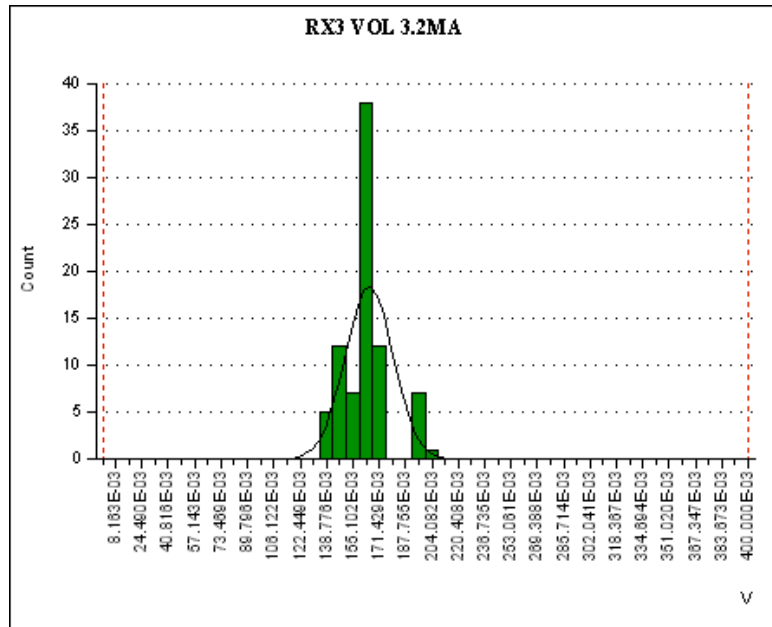
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.002, Test.Name=RX3 VOL 3.2MA



Statistics: (V)

Max	203.854E-03	25%	153.700E-03	SpecHigh	400.000E-03
Mean	163.255E-03	10%	143.943E-03	SpecLow	0
Min	139.408E-03	N	82	PctWithinSpec	100.00
Range	64.446E-03	Cp	>4.0000	c	
StdDev	14.513E-03	Cpl	3.7497	PctDefSpec	0
W	0.8574	Cpu	>4.0000	NWithinSpec	82
WpValue	0.0000	Cpk	3.7497	NOutsideSpec	0
90%	169.593E-03	Skew	0.8885		
75%	167.153E-03	Kurtosis	1.2539		
Median	164.715E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

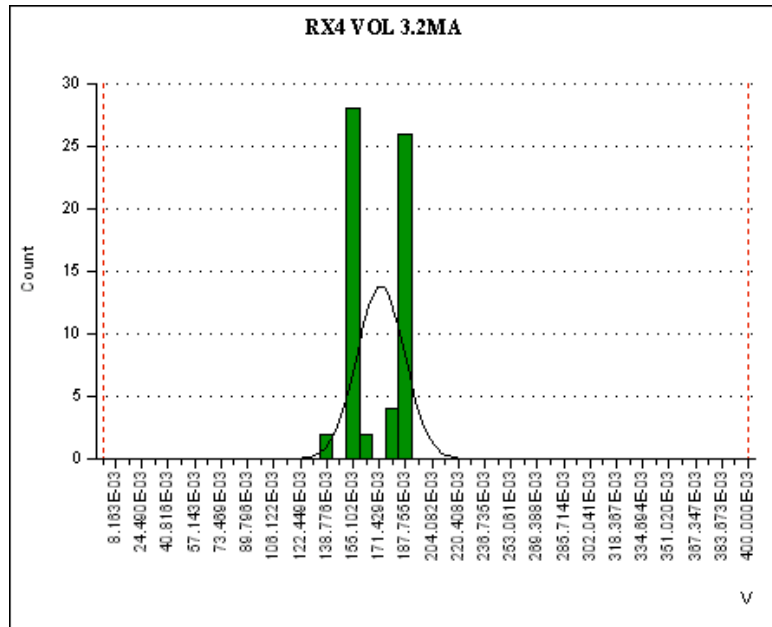
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.003, Test.Name=RX4 VOL 3.2MA



Statistics: (V)

Max	187.466E-03	25%	157.862E-03	SpecHigh	400.000E-03
Mean	170.323E-03	10%	157.214E-03	SpecLow	0
Min	138.034E-03	N	62	PctWithinSpec	100.00
Range	49.432E-03	Cp	>4.0000	c	
StdDev	14.547E-03	Cpl	3.9028	PctDefSpec	0
W	0.7637	Cpu	>4.0000	NWithinSpec	62
WpValue	0.0000	Cpk	3.9028	NOutsideSpec	0
90%	185.903E-03	Skew	-0.1644		
75%	184.416E-03	Kurtosis	-1.4760		
Median	159.692E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

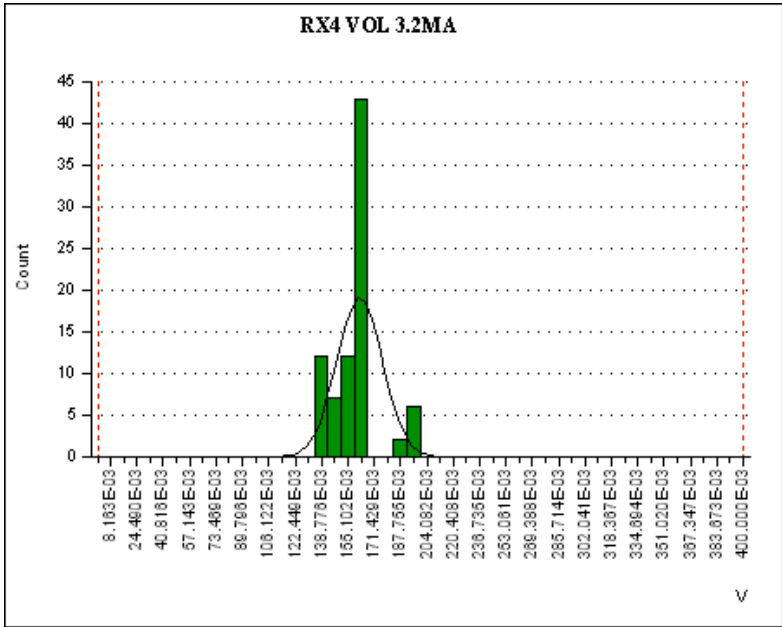
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.003, Test.Name=RX4 VOL 3.2MA



Statistics: (V)

Max	198.291E-03	25%	151.870E-03	SpecHigh	400.000E-03
Mean	160.380E-03	10%	141.504E-03	SpecLow	0
Min	136.627E-03	N	82	PctWithinSpec	100.00
Range	61.664E-03	Cp	>4.0000	c	
StdDev	13.994E-03	Cpl	3.8202	PctDefSpec	0
W	0.8639	Cpu	>4.0000	NWithinSpec	82
WpValue	0.0000	Cpk	3.8202	NOutsideSpec	0
90%	166.810E-03	Skew	0.8291		
75%	164.219E-03	Kurtosis	1.1680		
Median	161.855E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

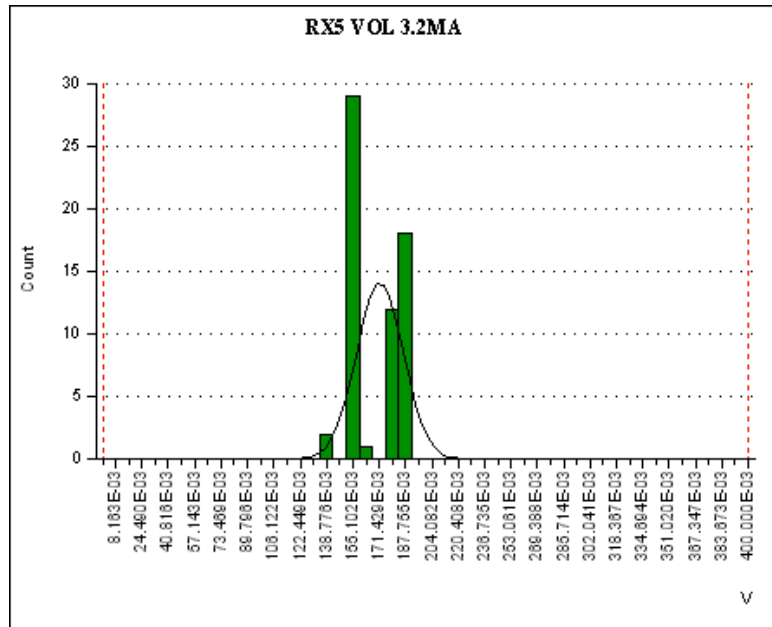
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=3.004, Test.Name=RX5 VOL 3.2MA



Statistics: (V)

Max	186.780E-03	25%	157.366E-03	SpecHigh	400.000E-03
Mean	169.815E-03	10%	157.099E-03	SpecLow	0
Min	138.339E-03	N	62	PctWithinSpec	100.00
Range	48.441E-03	Cp	>4.0000	c	
StdDev	14.300E-03	Cpl	3.9583	PctDefSpec	0
W	0.7606	Cpu	>4.0000	NWithinSpec	62
WpValue	0.0000	Cpk	3.9583	NOutsideSpec	0
90%	184.950E-03	Skew	-0.1616		
75%	184.111E-03	Kurtosis	-1.4900		
Median	159.349E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

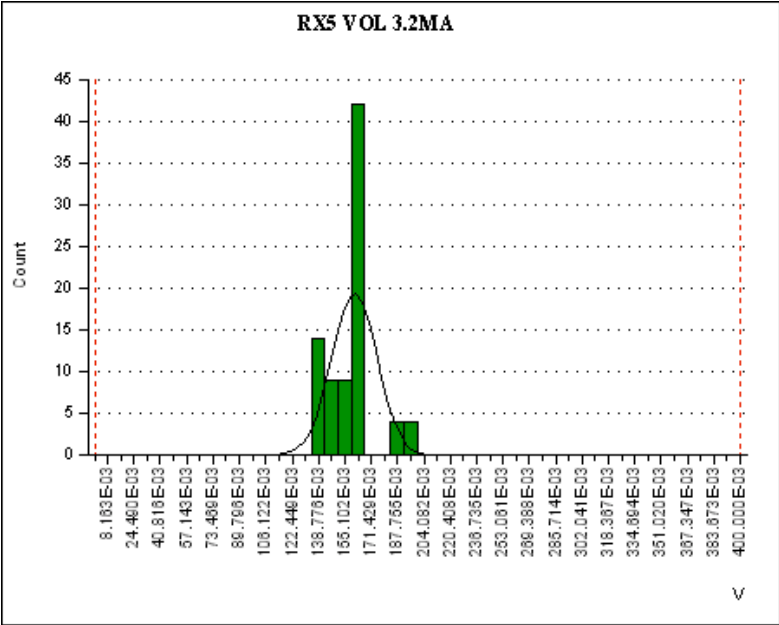
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.004, Test.Name=RX5 VOL 3.2MA



Statistics: (V)

Max	195.508E-03	25%	150.385E-03	SpecHigh	400.000E-03
Mean	159.053E-03	10%	141.046E-03	SpecLow	0
Min	136.055E-03	N	82	PctWithinSpec	100.00
Range	59.453E-03	Cp	>4.0000	c	
StdDev	13.712E-03	Cpl	3.8665	PctDefSpec	0
W	0.8647	Cpu	>4.0000	NWithinSpec	82
WpValue	0.0000	Cpk	3.8665	NOutsideSpec	0
90%	165.971E-03	Skew	0.8007		
75%	162.732E-03	Kurtosis	1.1044		
Median	160.446E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

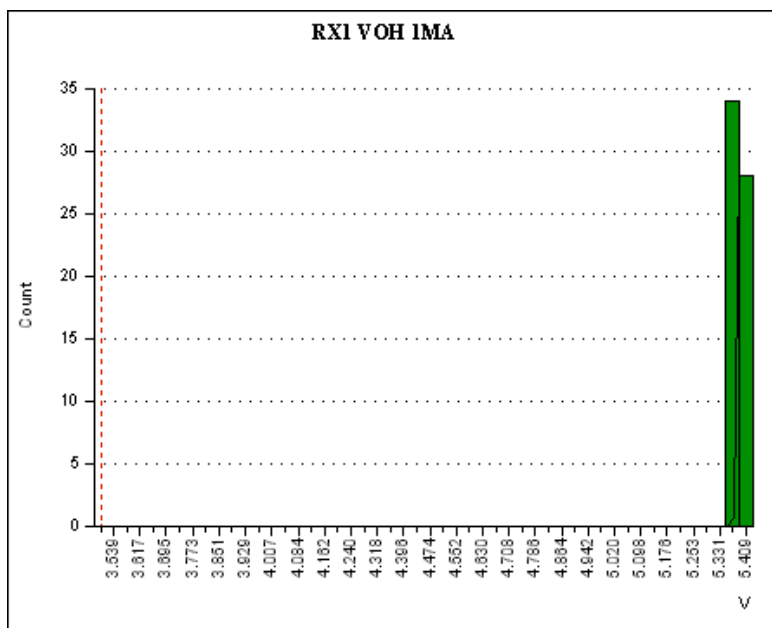
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=3.005, Test.Name=RX1 VOH 1MA



Statistics: (V)

Max	5.409	25%	5.379	SpecHigh	N/A
Mean	5.388	10%	5.376	SpecLow	3.500
Min	5.363	N	62	PctWithinSpec	100.00
Range	46.689E-03	Cp	N/A	PctDefSpec	0
StdDev	11.694E-03	Cpl	>4.0000	NWithinSpec	62
W	0.9639	Cpu	N/A	NOutsideSpec	0
WpValue	0.0655	Cpk	>4.0000		
90%	5.402	Skew	-0.0264		
75%	5.398	Kurtosis	-0.8229		
Median	5.385				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

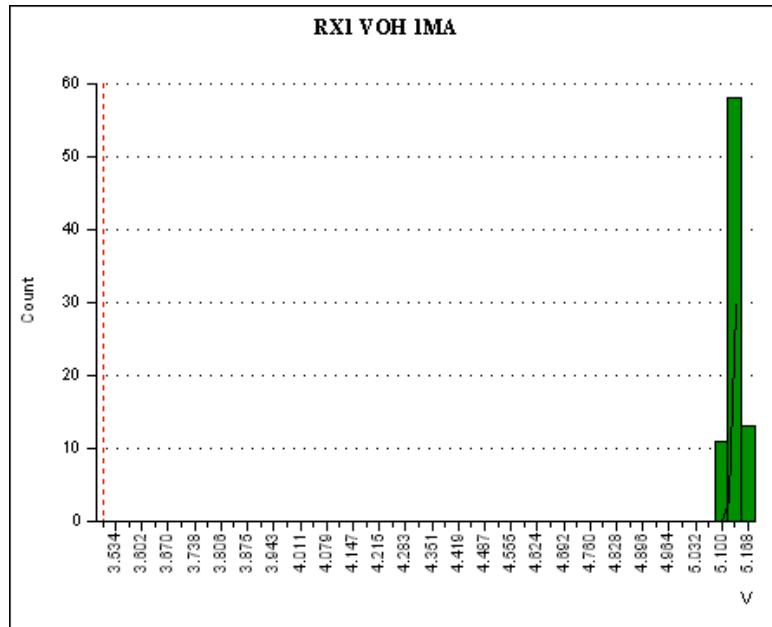
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.005, Test.Name=RX1 VOH 1MA



Statistics: (V)

Max	5.168	25%	5.131	SpecHigh	N/A
Mean	5.138	10%	5.116	SpecLow	3.500
Min	5.098	N	82	PctWithinSpec	100.00
Range	70.735E-03	Cp	N/A	PctDefSpec	0
StdDev	14.212E-03	Cpl	>4.0000	NWithinSpec	82
W	0.9751	Cpu	N/A	NOutsideSpec	0
WpValue	0.1117	Cpk	>4.0000		
90%	5.155	Skew	-0.4152		
75%	5.146	Kurtosis	0.2380		
Median	5.139				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

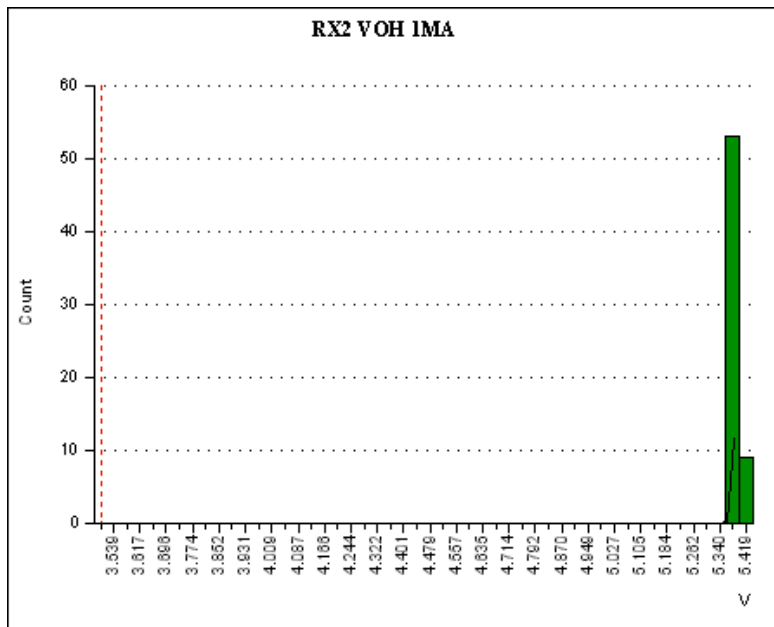
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.006, Test.Name=RX2 VOH 1MA



Statistics: (V)

Max	5.419	25%	5.377	SpecHigh	N/A
Mean	5.387	10%	5.369	SpecLow	3.500
Min	5.362	N	62	PctWithinSpec	100.00
Range	56.635E-03	Cp	N/A	PctDefSpec	0
StdDev	13.977E-03	Cpl	>4.0000	NWithinSpec	62
W	0.9756	Cpu	N/A	NOutsideSpec	0
WpValue	0.2536	Cpk	>4.0000		
90%	5.408	Skew	0.0965		
75%	5.397	Kurtosis	-0.6787		
Median	5.388				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

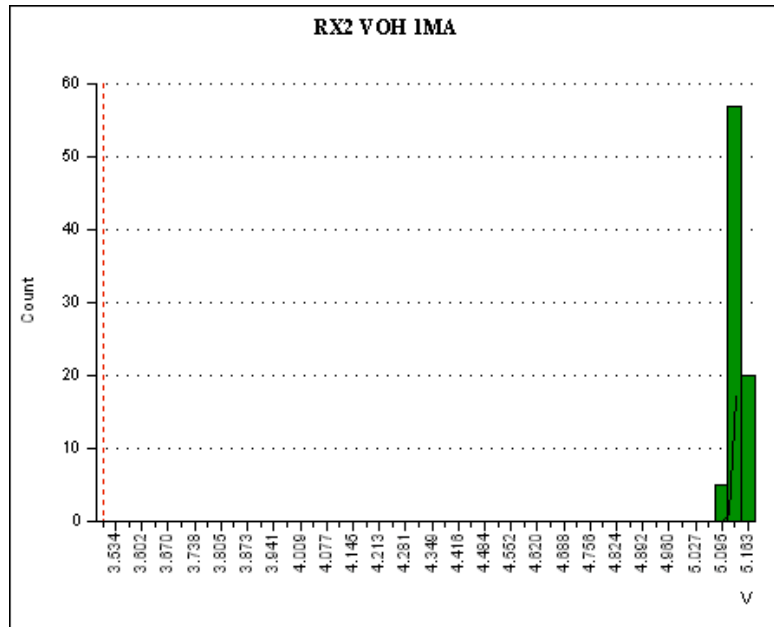
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.006, Test.Name=RX2 VOH 1MA



Statistics: (V)

Max	5.163	25%	5.132	SpecHigh	N/A
Mean	5.137	10%	5.117	SpecLow	3.500
Min	5.103	N	82	PctWithinSpec	100.00
Range	60.636E-03	Cp	N/A	PctDefSpec	0
StdDev	13.280E-03	Cpl	>4.0000	NWithinSpec	82
W	0.9560	Cpu	N/A	NOutsideSpec	0
WpValue	0.0068	Cpk	>4.0000		
90%	5.153	Skew	-0.6261		
75%	5.146	Kurtosis	0.3195		
Median	5.137				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

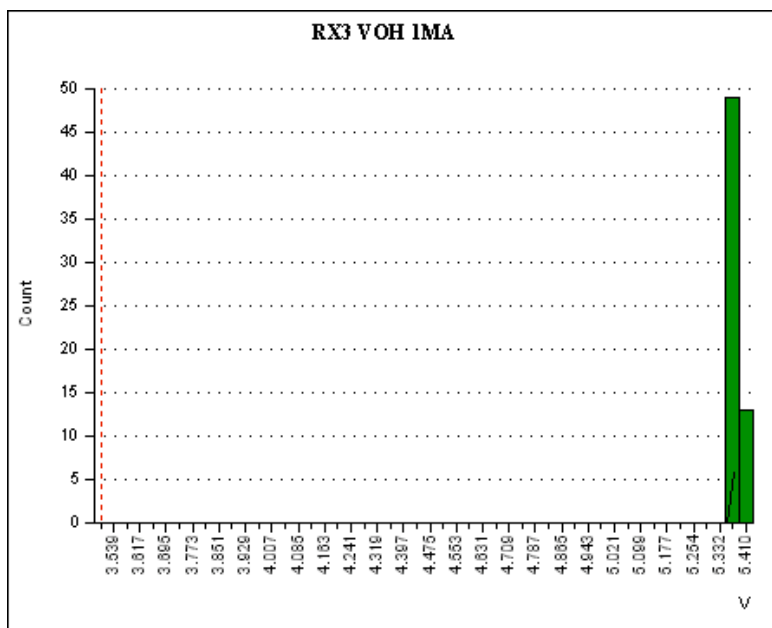
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.007, Test.Name=RX3 VOH 1MA



Statistics: (V)

Max	5.410	25%	5.372	SpecHigh	N/A
Mean	5.381	10%	5.367	SpecLow	3.500
Min	5.360	N	62	PctWithinSpec	100.00
Range	50.223E-03	Cp	N/A	PctDefSpec	0
StdDev	12.258E-03	Cpl	>4.0000	NWithinSpec	62
W	0.9735	Cpu	N/A	NOutsideSpec	0
WpValue	0.1988	Cpk	>4.0000		
90%	5.399	Skew	0.3500		
75%	5.389	Kurtosis	-0.6381		
Median	5.380				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

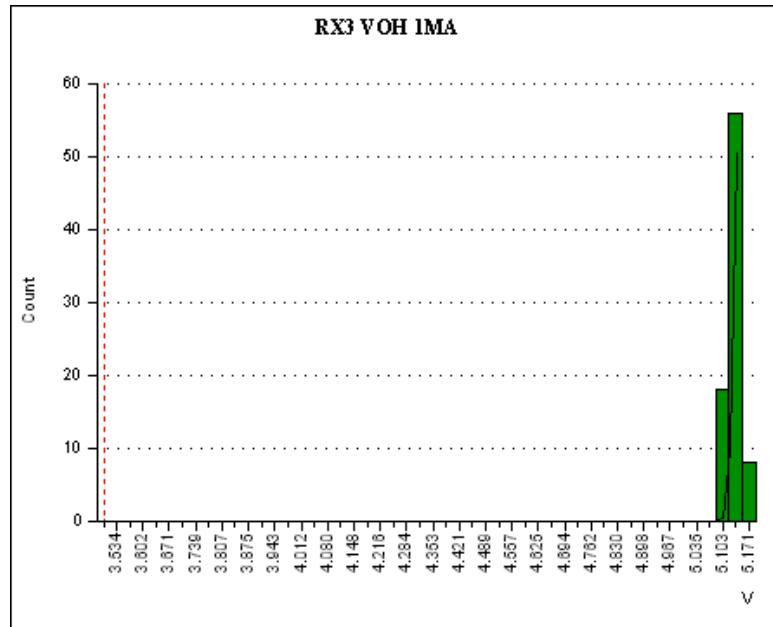
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
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Plot limits applied

NOutsidePlot

0

Test.Number=3.007, Test.Name=RX3 VOH 1MA



Statistics: (V)

Max	5.171	25%	5.126	SpecHigh	N/A
Mean	5.134	10%	5.115	SpecLow	3.500
Min	5.102	N	82	PctWithinSpec	100.00
Range	69.210E-03	Cp	N/A	PctDefSpec	0
StdDev	14.815E-03	Cpl	>4.0000	NWithinSpec	82
W	0.9845	Cpu	N/A	NOutsideSpec	0
WpValue	0.4259	Cpk	>4.0000		
90%	5.151	Skew	-0.0616		
75%	5.143	Kurtosis	-0.1488		
Median	5.136				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

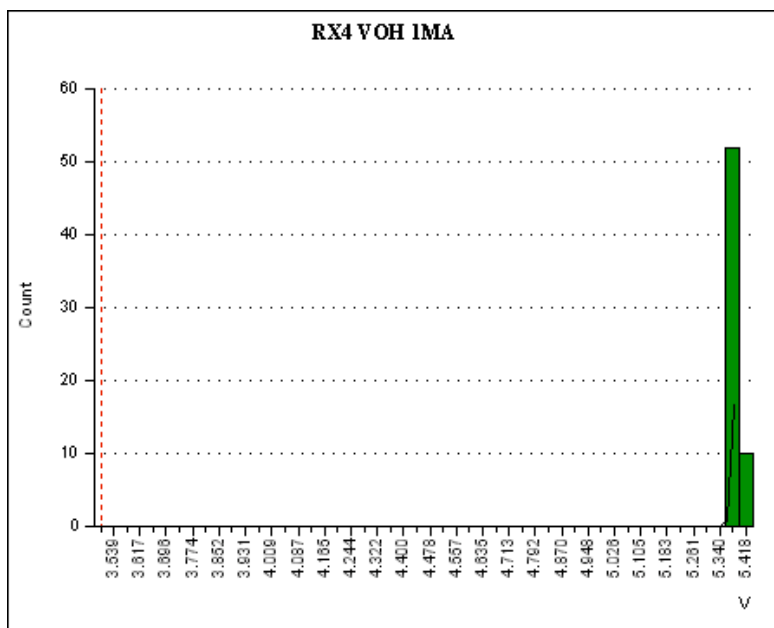
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=3.008, Test.Name=RX4 VOH 1MA



Statistics: (V)

Max	5.418	25%	5.373	SpecHigh	N/A
Mean	5.385	10%	5.366	SpecLow	3.500
Min	5.362	N	62	PctWithinSpec	100.00
Range	56.138E-03	Cp	N/A	PctDefSpec	0
StdDev	14.721E-03	Cpl	>4.0000	NWithinSpec	62
W	0.9553	Cpu	N/A	NOutsideSpec	0
WpValue	0.0241	Cpk	>4.0000		
90%	5.406	Skew	0.3920		
75%	5.396	Kurtosis	-0.7016		
Median	5.382				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

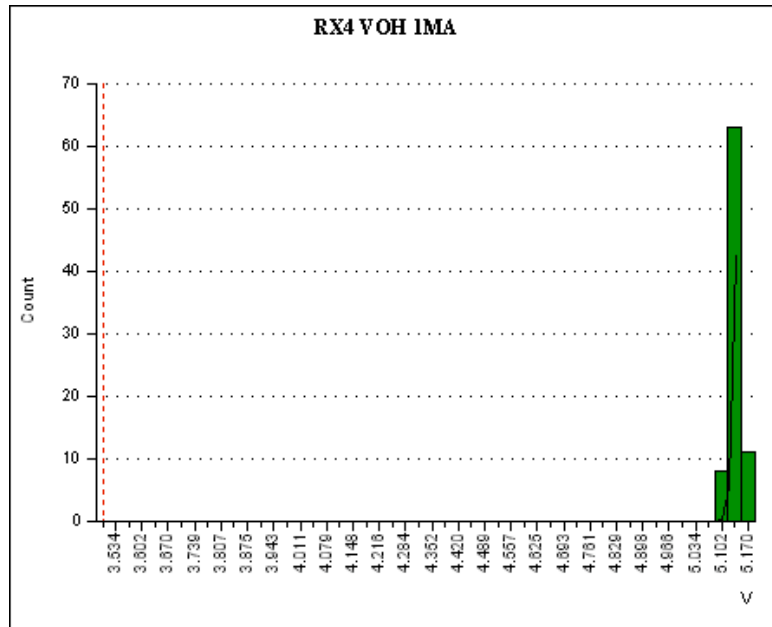
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.008, Test.Name=RX4 VOH 1MA



Statistics: (V)

Max	5.170	25%	5.124	SpecHigh	N/A
Mean	5.136	10%	5.119	SpecLow	3.500
Min	5.106	N	82	PctWithinSpec	100.00
Range	64.524E-03	Cp	N/A	PctDefSpec	0
StdDev	14.024E-03	Cpl	>4.0000	NWithinSpec	82
W	0.9838	Cpu	N/A	NOutsideSpec	0
WpValue	0.3928	Cpk	>4.0000		
90%	5.156	Skew	0.0730		
75%	5.147	Kurtosis	-0.6656		
Median	5.137				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T		0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T		0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T		0

Data: Raw Data

Stat limits applied

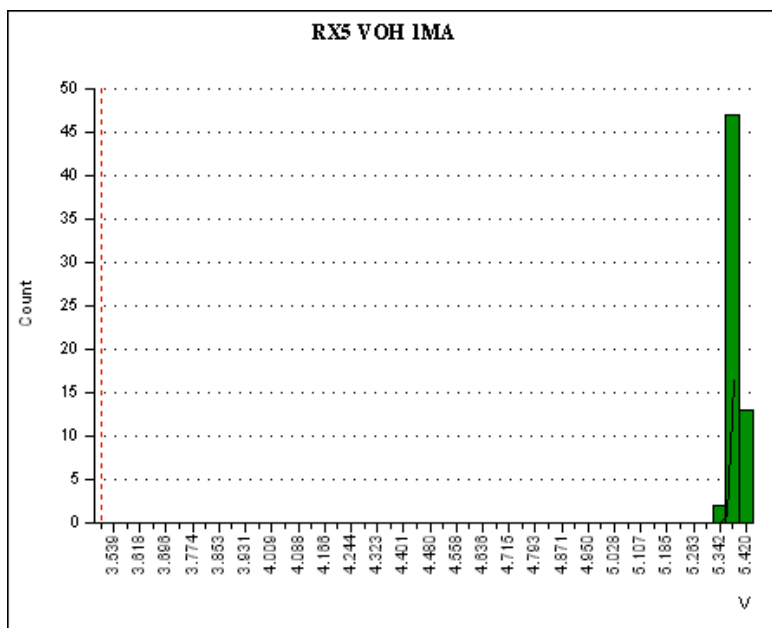
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.009, Test.Name=RX5 VOH 1MA



Statistics: (V)

Max	5.420	25%	5.376	SpecHigh	N/A
Mean	5.387	10%	5.368	SpecLow	3.500
Min	5.358	N	62	PctWithinSpec	100.00
Range	62.201E-03	Cp	N/A	PctDefSpec	0
StdDev	14.686E-03	Cpl	>4.0000	NWithinSpec	62
W	0.9850	Cpu	N/A	NOutsideSpec	0
WpValue	0.6489	Cpk	>4.0000		
90%	5.407	Skew	0.1075		
75%	5.397	Kurtosis	-0.7138		
Median	5.386				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

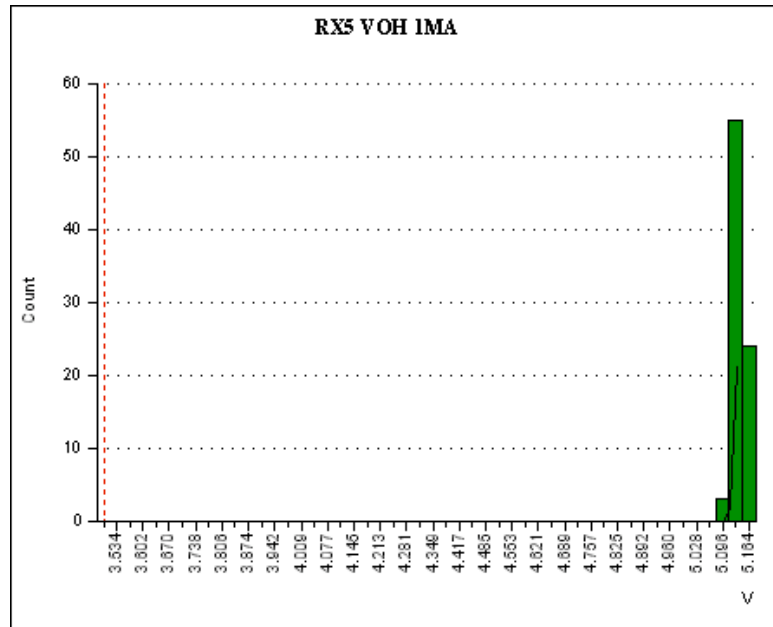
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=3.009, Test.Name=RX5 VOH 1MA



Statistics: (V)

Max	5.164	25%	5.126	SpecHigh	N/A
Mean	5.138	10%	5.118	SpecLow	3.500
Min	5.097	N	82	PctWithinSpec	100.00
Range	67.610E-03	Cp	N/A	PctDefSpec	0
StdDev	14.651E-03	Cpl	>4.0000	NWithinSpec	82
W	0.9824	Cpu	N/A	NOutsideSpec	0
WpValue	0.3221	Cpk	>4.0000		
90%	5.156	Skew	-0.3041		
75%	5.149	Kurtosis	-0.2928		
Median	5.137				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

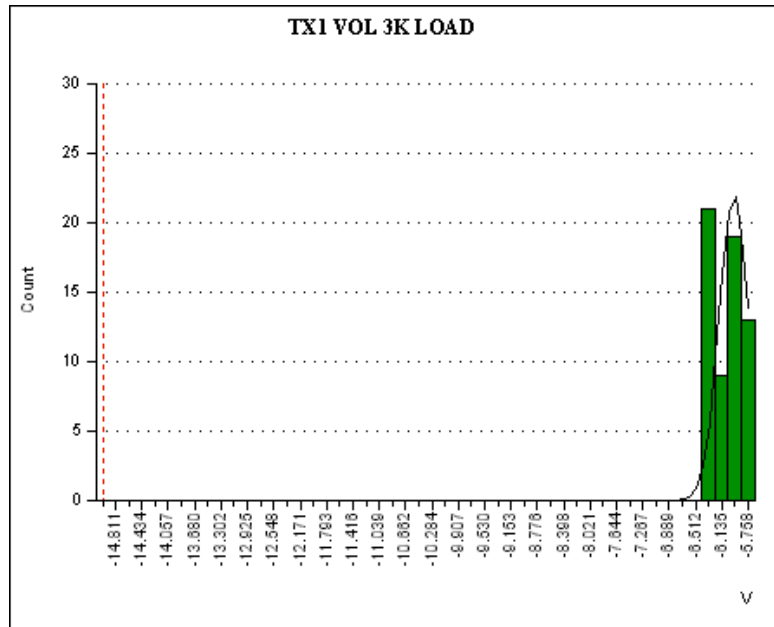
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=4.000, Test.Name=TX1 VOL 3K LOAD



Statistics: (V)

Max	-5.758	25%	-6.266	SpecHigh	N/A
Mean	-6.054	10%	-6.306	SpecLow	-15.000
Min	-6.374	N	62	PctWithinSpec	100.00
Range	616.510E-03	Cp	N/A	PctDefSpec	0
StdDev	212.349E-03	Cpl	>4.0000	NWithinSpec	62
W	0.8476	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	-5.804	Skew	-0.1084		
75%	-5.861	Kurtosis	-1.7643		
Median	-5.942				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

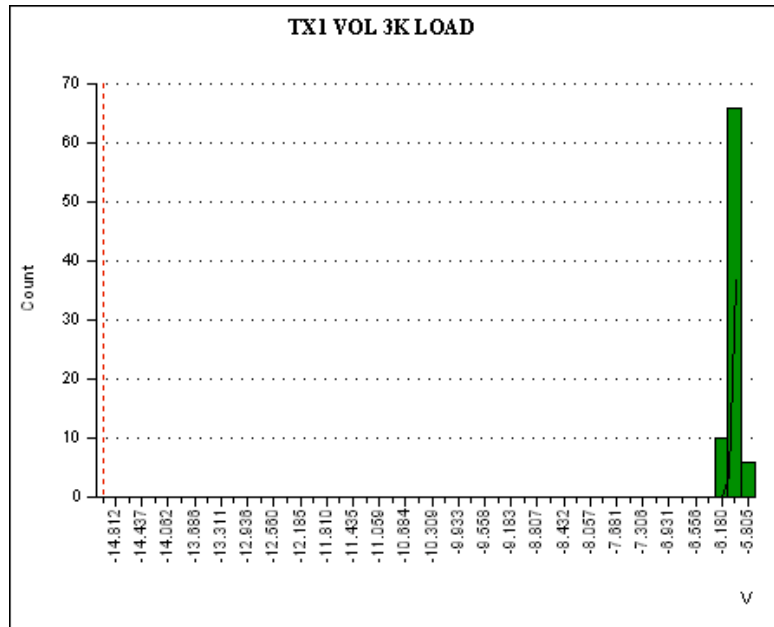
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.000, Test.Name=TX1 VOL 3K LOAD



Statistics: (V)

Max	-5.805	25%	-6.038	SpecHigh	N/A
Mean	-5.986	10%	-6.096	SpecLow	-15.000
Min	-6.158	N	82	PctWithinSpec	100.00
Range	352.960E-03	Cp	N/A	PctDefSpec	0
StdDev	74.376E-03	Cpl	>4.0000	NWithinSpec	82
W	0.9790	Cpu	N/A	NOutsideSpec	0
WpValue	0.1980	Cpk	>4.0000		
90%	-5.913	Skew	-0.0951		
75%	-5.935	Kurtosis	-0.0421		
Median	-5.978				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

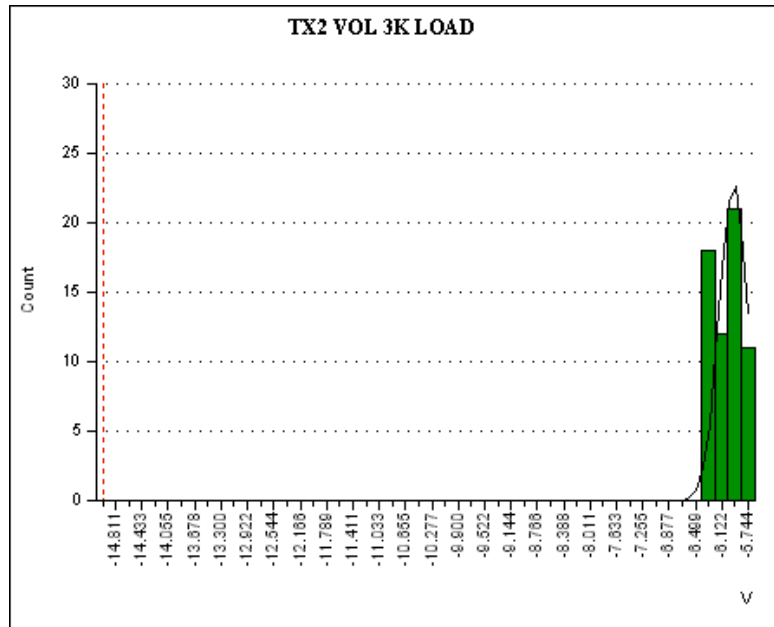
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.001, Test.Name=TX2 VOL 3K LOAD



Statistics: (V)

Max	-5.744	25%	-6.256	SpecHigh	N/A
Mean	-6.045	10%	-6.296	SpecLow	-15.000
Min	-6.384	N	62	PctWithinSpec	100.00
Range	640.659E-03	Cp	N/A	PctDefSpec	0
StdDev	205.408E-03	Cpl	>4.0000	NWithinSpec	62
W	0.8732	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	-5.803	Skew	-0.1854		
75%	-5.862	Kurtosis	-1.6386		
Median	-5.948				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

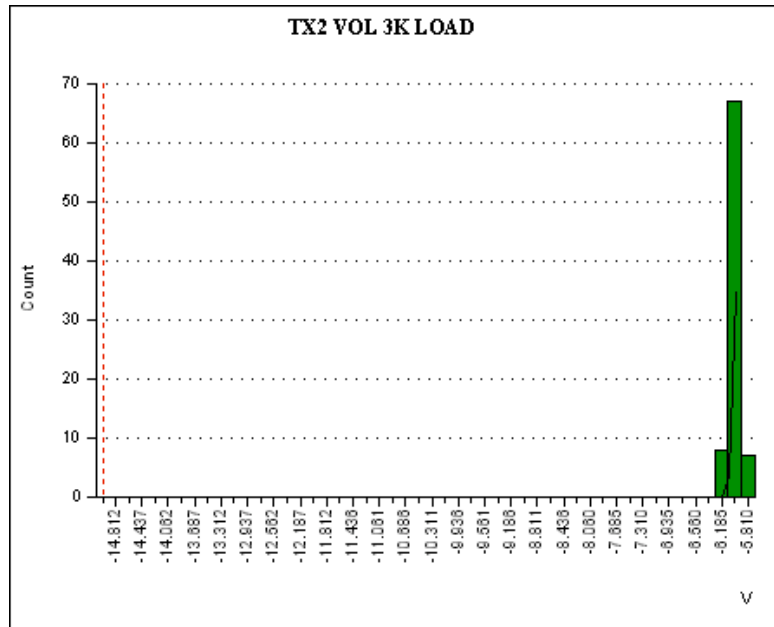
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.001, Test.Name=TX2 VOL 3K LOAD



Statistics: (V)

Max	-5.810	25%	-6.046	SpecHigh	N/A
Mean	-5.987	10%	-6.090	SpecLow	-15.000
Min	-6.149	N	82	PctWithinSpec	100.00
Range	339.401E-03	Cp	N/A	PctDefSpec	0
StdDev	75.952E-03	Cpl	>4.0000	NWithinSpec	82
W	0.9742	Cpu	N/A	NOutsideSpec	0
WpValue	0.0966	Cpk	>4.0000		
90%	-5.913	Skew	-0.2083		
75%	-5.933	Kurtosis	-0.3415		
Median	-5.969				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

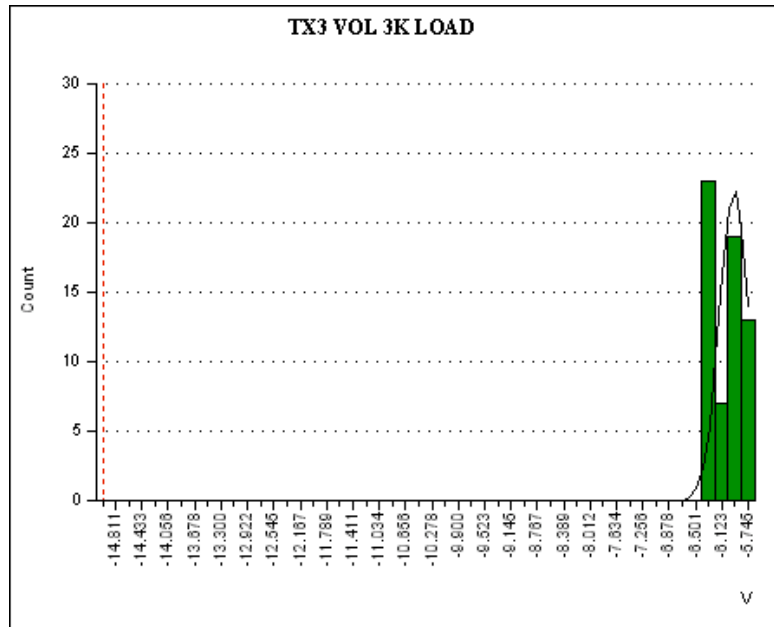
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.002, Test.Name=TX3 VOL 3K LOAD



Statistics: (V)

Max	-5.745	25%	-6.236	SpecHigh	N/A
Mean	-6.041	10%	-6.305	SpecLow	-15.000
Min	-6.370	N	62	PctWithinSpec	100.00
Range	624.738E-03	Cp	N/A	PctDefSpec	0
StdDev	208.868E-03	Cpl	>4.0000	NWithinSpec	62
W	0.8642	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	-5.804	Skew	-0.1354		
75%	-5.854	Kurtosis	-1.6965		
Median	-5.941				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

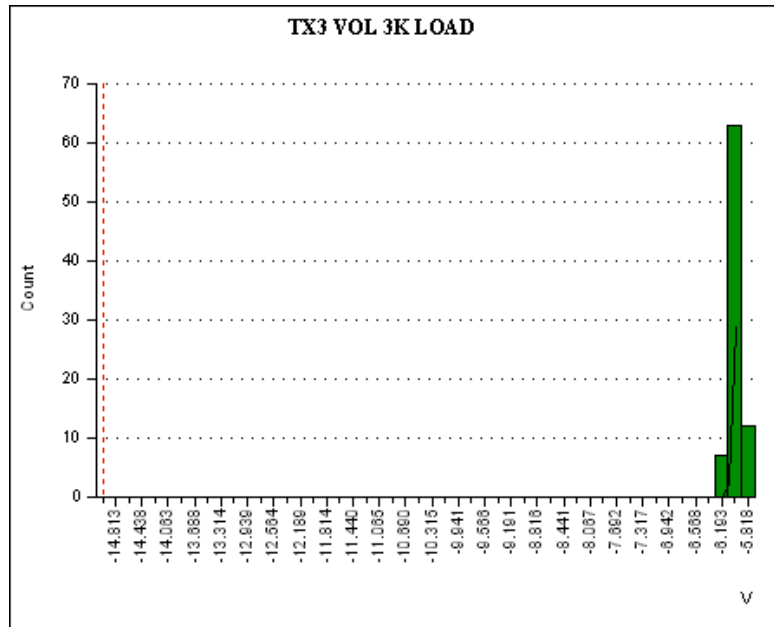
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.002, Test.Name=TX3 VOL 3K LOAD



Statistics: (V)

Max	-5.818	25%	-6.046	SpecHigh	N/A
Mean	-5.985	10%	-6.096	SpecLow	-15.000
Min	-6.170	N	82	PctWithinSpec	100.00
Range	351.665E-03	Cp	N/A	PctDefSpec	0
StdDev	74.657E-03	Cpl	>4.0000	NWithinSpec	82
W	0.9725	Cpu	N/A	NOutsideSpec	0
WpValue	0.0752	Cpk	>4.0000		
90%	-5.899	Skew	-0.3541		
75%	-5.934	Kurtosis	-0.3865		
Median	-5.966				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

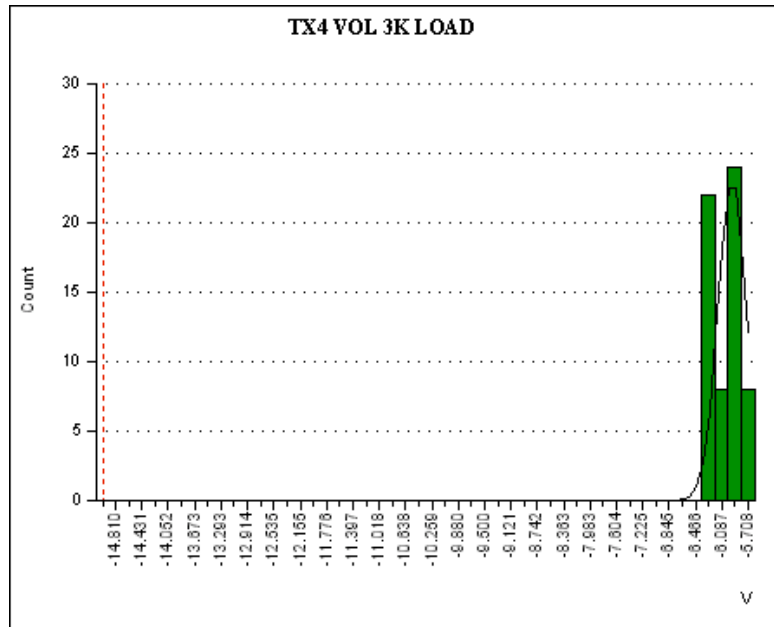
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.003, Test.Name=TX4 VOL 3K LOAD



Statistics: (V)

Max	-5.708	25%	-6.222	SpecHigh	N/A
Mean	-6.031	10%	-6.281	SpecLow	-15.000
Min	-6.347	N	62	PctWithinSpec	100.00
Range	639.289E-03	Cp	N/A	PctDefSpec	0
StdDev	203.112E-03	Cpl	>4.0000	NWithinSpec	62
W	0.8703	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	-5.795	Skew	-0.1140		
75%	-5.854	Kurtosis	-1.6803		
Median	-5.941				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

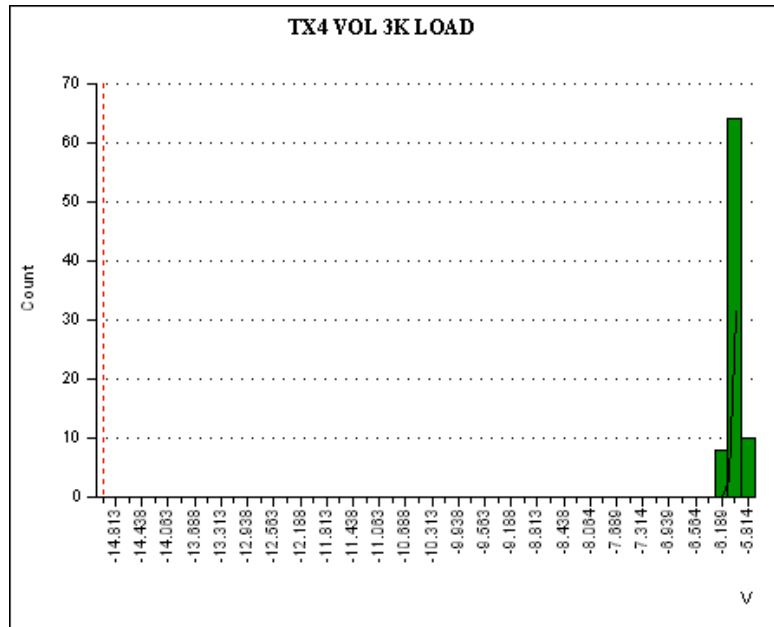
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.003, Test.Name=TX4 VOL 3K LOAD



Statistics: (V)

Max	-5.814	25%	-6.035	SpecHigh	N/A
Mean	-5.984	10%	-6.094	SpecLow	-15.000
Min	-6.183	N	82	PctWithinSpec	100.00
Range	368.876E-03	Cp	N/A	PctDefSpec	0
StdDev	76.802E-03	Cpl	>4.0000	NWithinSpec	82
W	0.9825	Cpu	N/A	NOutsideSpec	0
WpValue	0.3272	Cpk	>4.0000		
90%	-5.904	Skew	-0.2327		
75%	-5.927	Kurtosis	-0.2518		
Median	-5.967				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

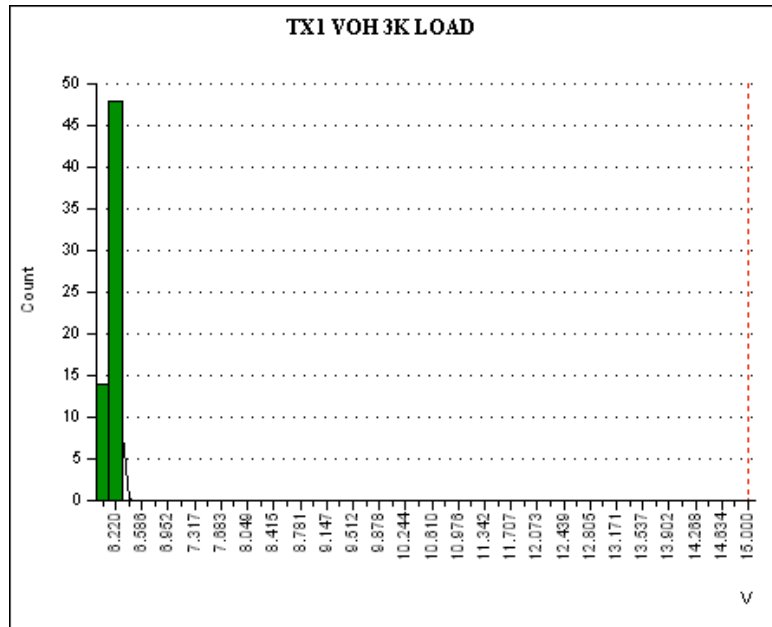
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.004, Test.Name=TX1 VOH 3K LOAD



Statistics: (V)

Max	6.308	25%	6.135	SpecHigh	15.000
Mean	6.175	10%	6.086	SpecLow	N/A
Min	6.037	N	62	PctWithinSpec	100.00
Range	270.867E-03	Cp	N/A	c	
StdDev	62.041E-03	Cpl	N/A	PctDefSpec	0
W	0.9849	Cpu	>4.0000	NWithinSpec	62
WpValue	0.6429	Cpk	>4.0000	NOutsideSpec	0
90%	6.264	Skew	0.0235		
75%	6.212	Kurtosis	-0.5820		
Median	6.176				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

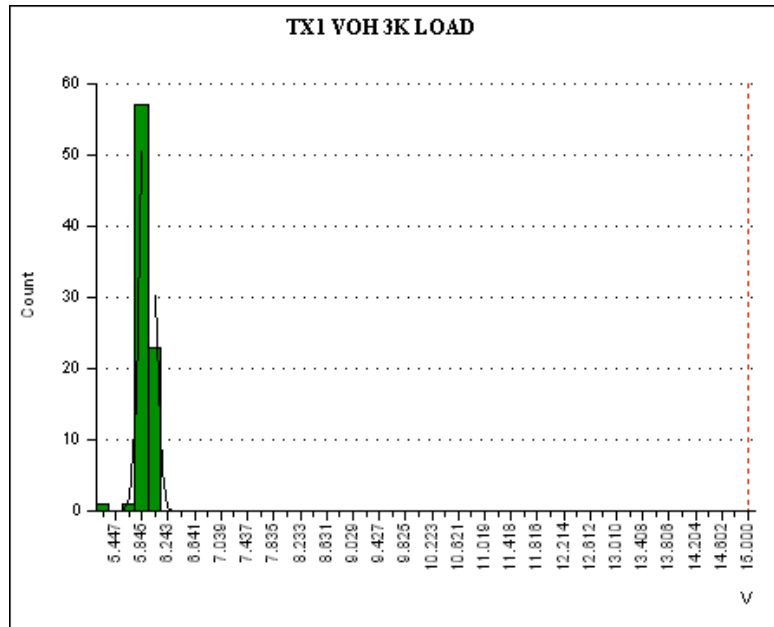
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.004, Test.Name=TX1 VOH 3K LOAD



Statistics: (V)

Max	6.085	25%	5.868	SpecHigh	15.000
Mean	5.905	10%	5.826	SpecLow	N/A
Min	5.248	N	82	PctWithinSpec	100.00
Range	837.157E-03	Cp	N/A	PctDefSpec	0
StdDev	99.251E-03	Cpl	N/A	NWithinSpec	82
W	0.7353	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	5.993	Skew	-3.5925		
75%	5.958	Kurtosis	23.0758		
Median	5.919				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

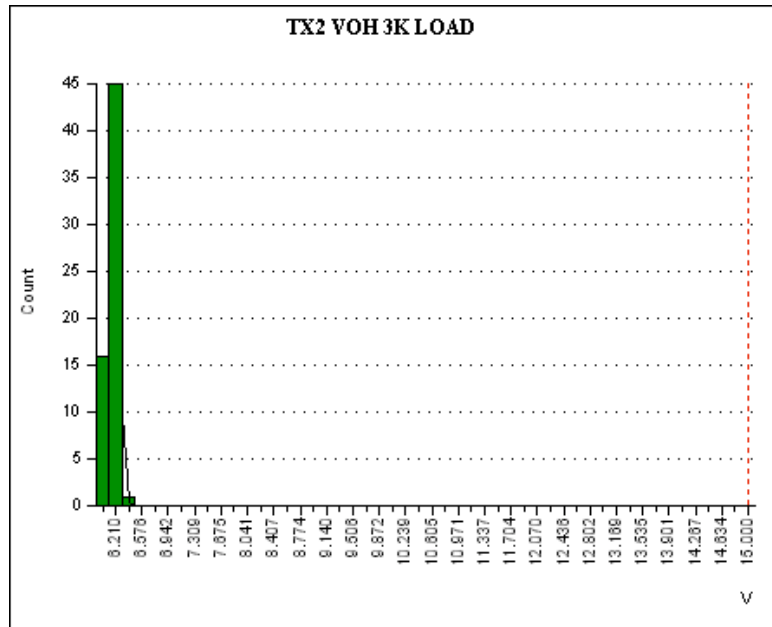
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.005, Test.Name=TX2 VOH 3K LOAD



Statistics: (V)

Max	6.319	25%	6.116	SpecHigh	15.000
Mean	6.164	10%	6.074	SpecLow	N/A
Min	6.027	N	62	PctWithinSpec	100.00
Range	292.195E-03	Cp	N/A	PctDefSpec	0
StdDev	67.390E-03	Cpl	N/A	NWithinSpec	62
W	0.9842	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.6070	Cpk	>4.0000		
90%	6.259	Skew	-0.0353		
75%	6.216	Kurtosis	-0.6302		
Median	6.161				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

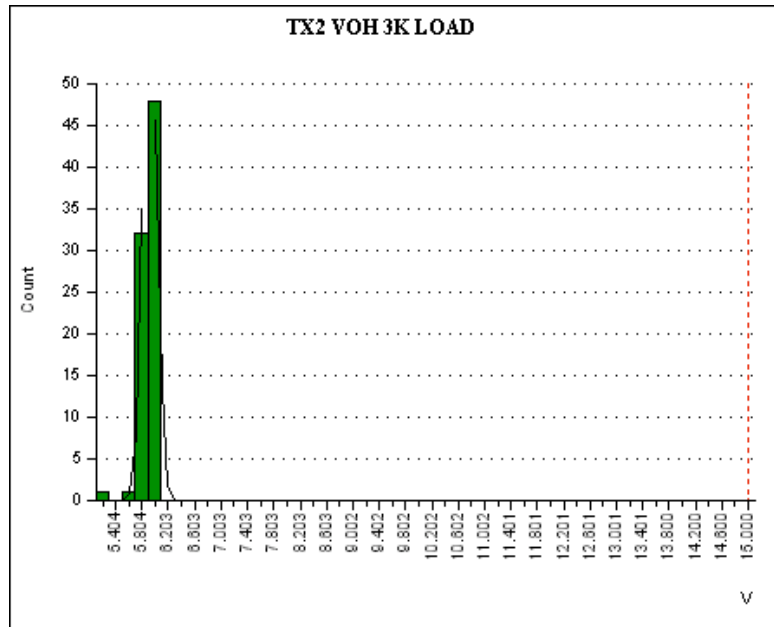
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.005, Test.Name=TX2 VOH 3K LOAD



Statistics: (V)

Max	6.094	25%	5.868	SpecHigh	15.000
Mean	5.904	10%	5.822	SpecLow	N/A
Min	5.204	N	82	PctWithinSpec	100.00
Range	890.321E-03	Cp	N/A	PctDefSpec	0
StdDev	103.409E-03	Cpl	N/A	NWithinSpec	82
W	0.7086	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	5.999	Skew	-3.8853		
75%	5.950	Kurtosis	25.5019		
Median	5.917				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

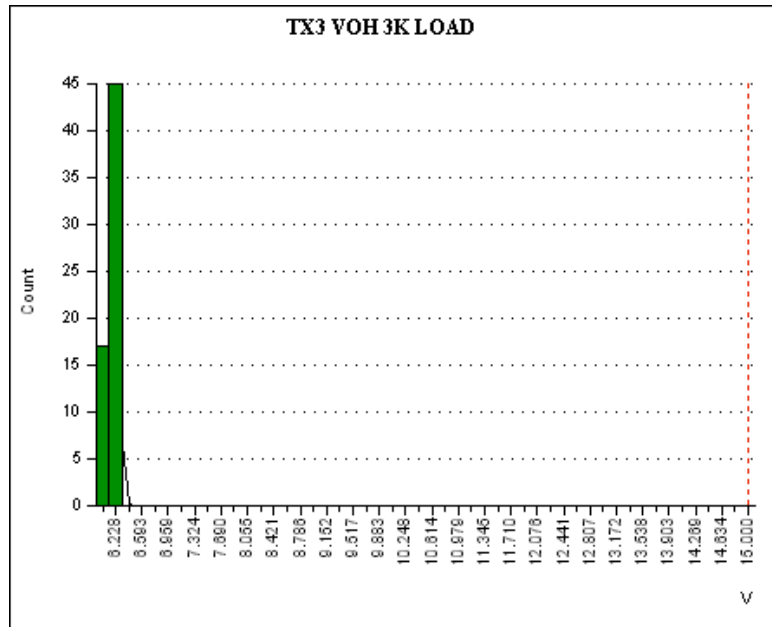
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.006, Test.Name=TX3 VOH 3K LOAD



Statistics: (V)

Max	6.282	25%	6.130	SpecHigh	15.000
Mean	6.171	10%	6.071	SpecLow	N/A
Min	6.045	N	62	PctWithinSpec	100.00
Range	237.328E-03	Cp	N/A	PctDefSpec	0
StdDev	66.079E-03	Cpl	N/A	NWithinSpec	62
W	0.9632	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0603	Cpk	>4.0000		
90%	6.262	Skew	-0.1989		
75%	6.218	Kurtosis	-0.7578		
Median	6.174				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

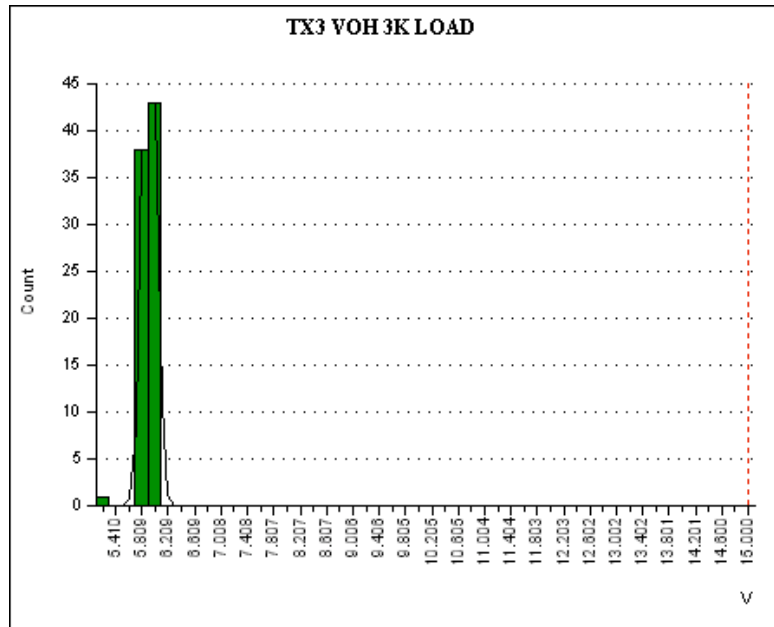
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.006, Test.Name=TX3 VOH 3K LOAD



Statistics: (V)

Max	6.062	25%	5.863	SpecHigh	15.000
Mean	5.902	10%	5.824	SpecLow	N/A
Min	5.210	N	82	PctWithinSpec	100.00
Range	851.853E-03	Cp	N/A	PctDefSpec	0
StdDev	99.853E-03	Cpl	N/A	NWithinSpec	82
W	0.6820	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	5.986	Skew	-4.1996		
75%	5.953	Kurtosis	28.0530		
Median	5.916				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

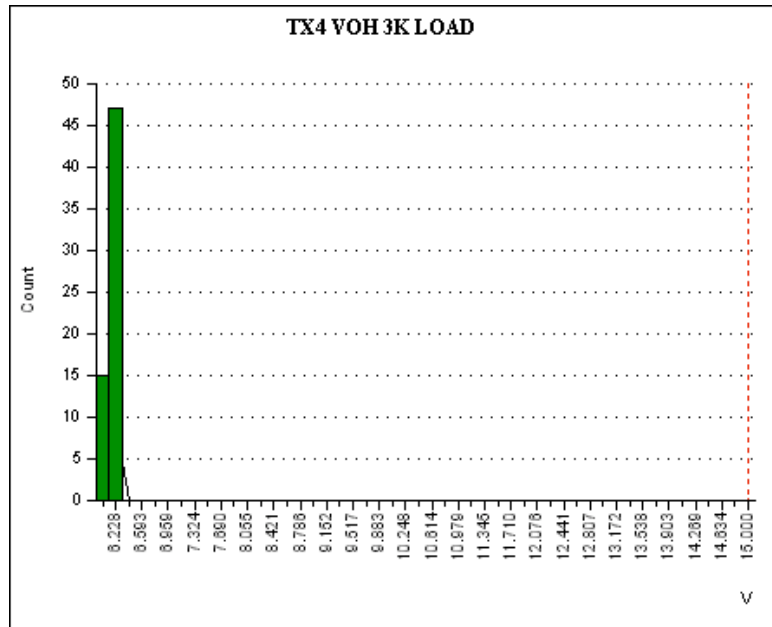
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.007, Test.Name=TX4 VOH 3K LOAD



Statistics: (V)

Max	6.280	25%	6.138	SpecHigh	15.000
Mean	6.170	10%	6.076	SpecLow	N/A
Min	6.045	N	62	PctWithinSpec	100.00
Range	234.677E-03	Cp	N/A	c	
StdDev	60.613E-03	Cpl	N/A	PctDefSpec	0
W	0.9650	Cpu	>4.0000	NWithinSpec	62
WpValue	0.0745	Cpk	>4.0000	NOutsideSpec	0
90%	6.243	Skew	-0.3742		
75%	6.214	Kurtosis	-0.6246		
Median	6.174				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

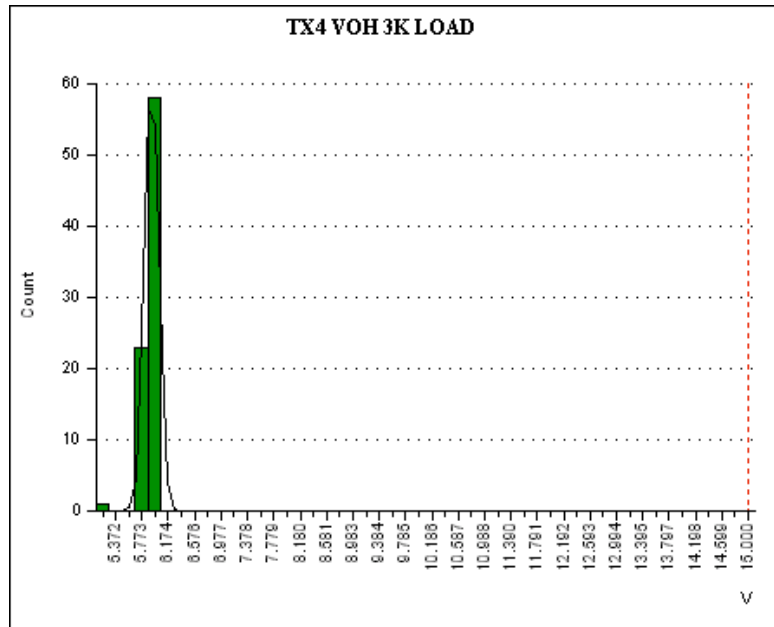
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=4.007, Test.Name=TX4 VOH 3K LOAD



Statistics: (V)

Max	6.056	25%	5.866	SpecHigh	15.000
Mean	5.904	10%	5.813	SpecLow	N/A
Min	5.172	N	82	PctWithinSpec	100.00
Range	884.228E-03	Cp	N/A	c	
StdDev	106.379E-03	Cpl	N/A	PctDefSpec	0
W	0.6857	Cpu	>4.0000	NWithinSpec	82
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	5.987	Skew	-4.1424		
75%	5.957	Kurtosis	27.2821		
Median	5.917				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

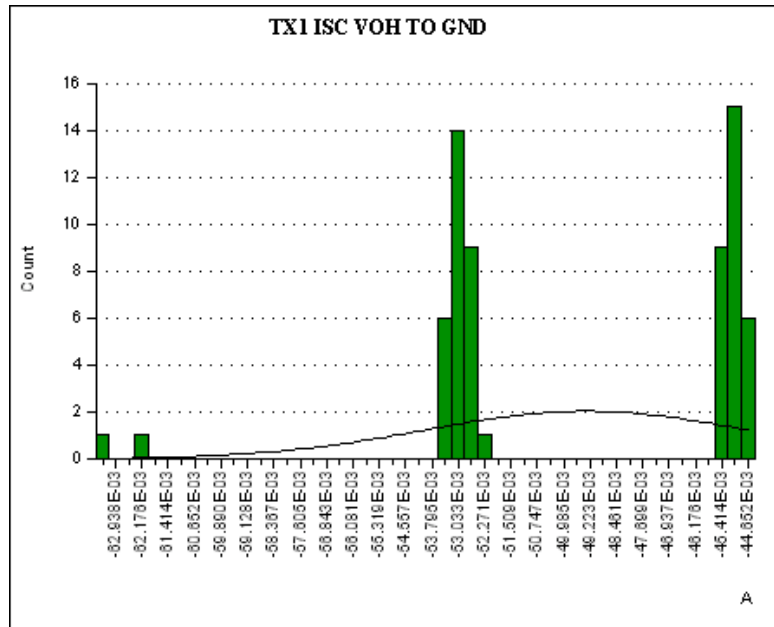
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=5.000, Test.Name=TX1 ISC VOH TO GND



Statistics: (A)

Max	-44.652E-03	25%	-53.010E-03	SpecHigh	N/A
Mean	-49.474E-03	10%	-53.251E-03	SpecLow	N/A
Min	-63.319E-03	N	62	PctWithinSpec	N/A
Range	18.667E-03	Cp	N/A	c	
StdDev	4.616E-03	Cpl	N/A	PctDefSpec	N/A
W	0.7557	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	-44.859E-03	Skew	-0.5925		
75%	-45.111E-03	Kurtosis	-0.0321		
Median	-52.502E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

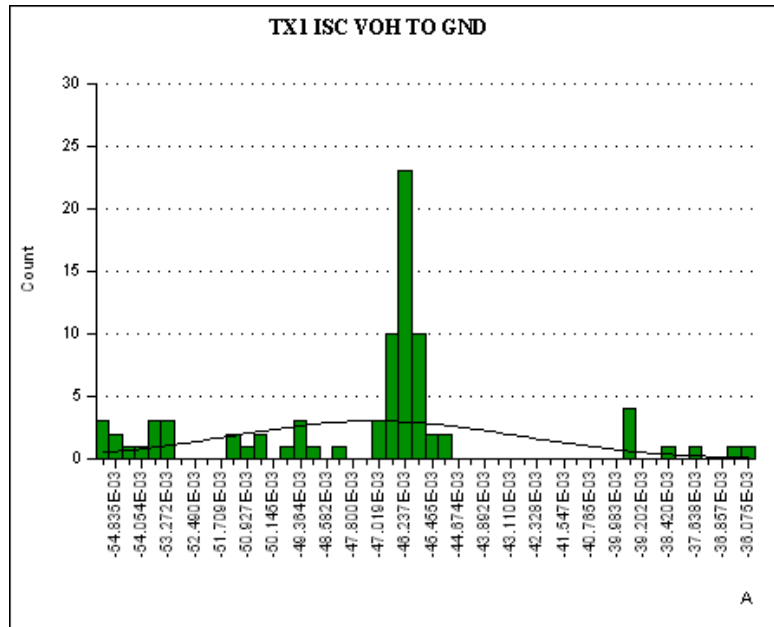
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=5.000, Test.Name=TX1 ISC VOH TO GND



Statistics: (A)

Max	-36.075E-03	25%	-49.374E-03	SpecHigh	N/A
Mean	-47.202E-03	10%	-53.545E-03	SpecLow	N/A
Min	-55.226E-03	N	82	PctWithinSpec	N/A
Range	19.151E-03	Cp	N/A	c	
StdDev	4.208E-03	Cpl	N/A	PctDefSpec	N/A
W	0.8696	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	-45.123E-03	Skew	0.1867		
75%	-45.988E-03	Kurtosis	0.7353		
Median	-46.332E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

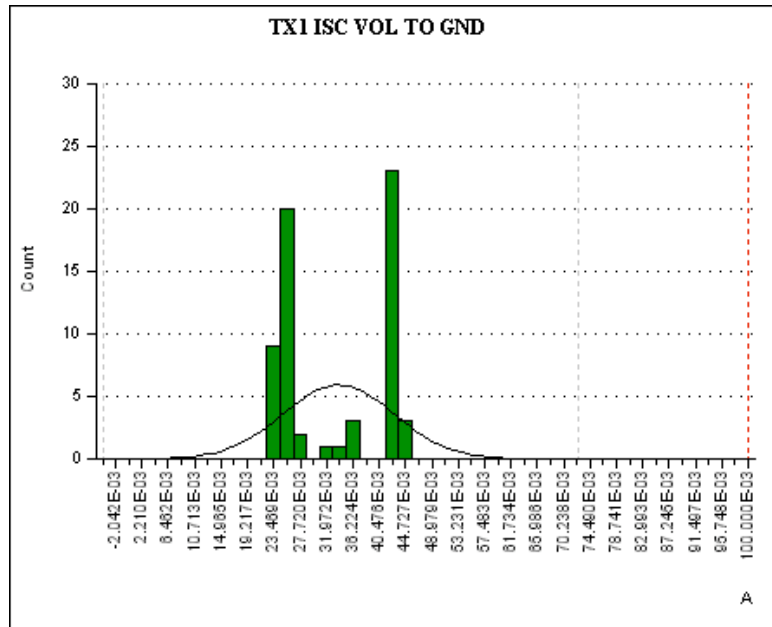
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=5.004, Test.Name=TX1 ISC VOL TO GND



Statistics: (A)

Max	43.864E-03	25%	24.779E-03	SpecHigh	100.000E-03
Mean	33.515E-03	10%	24.436E-03	SpecLow	N/A
Min	24.183E-03	N	62	PctWithinSpec	100.00
Range	19.681E-03	Cp	N/A	c	
StdDev	8.883E-03	Cpl	N/A	PctDefSpec	0
W	0.7232	Cpu	2.4948	NWithinSpec	62
WpValue	0.0000	Cpk	2.4948	NOutsideSpec	0
90%	43.492E-03	Skew	0.1189		
75%	43.290E-03	Kurtosis	-1.9470		
Median	30.342E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

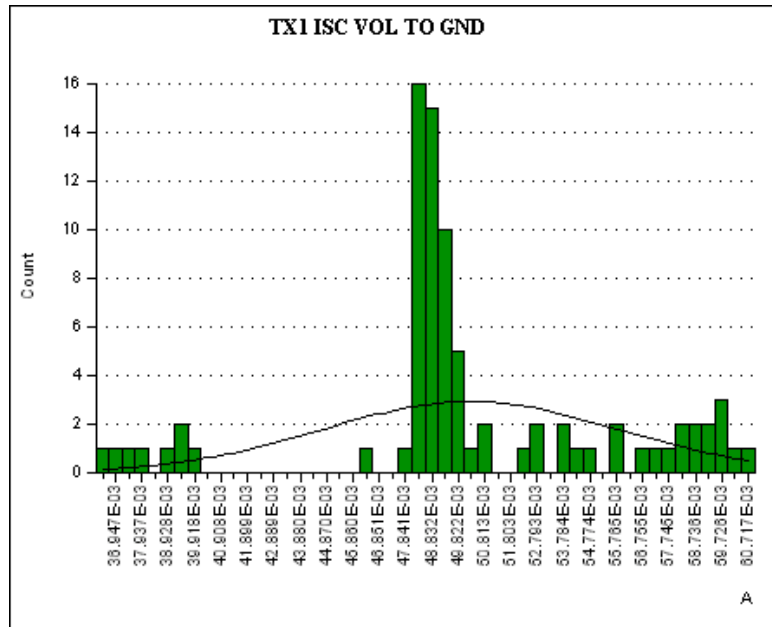
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
72.653E-03	-4.168E-03	100.00	0	62	0

Plot limits applied

NOutsidePlot

0

Test.Number=5.001, Test.Name=TX1 ISC VOL TO GND



Statistics: (A)

Max	60.717E-03	25%	48.462E-03	SpecHigh	N/A
Mean	50.140E-03	10%	46.362E-03	SpecLow	N/A
Min	36.452E-03	N	82	PctWithinSpec	N/A
Range	24.265E-03	Cp	N/A	PctDefSpec	N/A
StdDev	5.529E-03	Cpl	N/A	NWithinSpec	N/A
W	0.8737	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	58.496E-03	Skew	-0.2403		
75%	52.634E-03	Kurtosis	0.6058		
Median	49.080E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

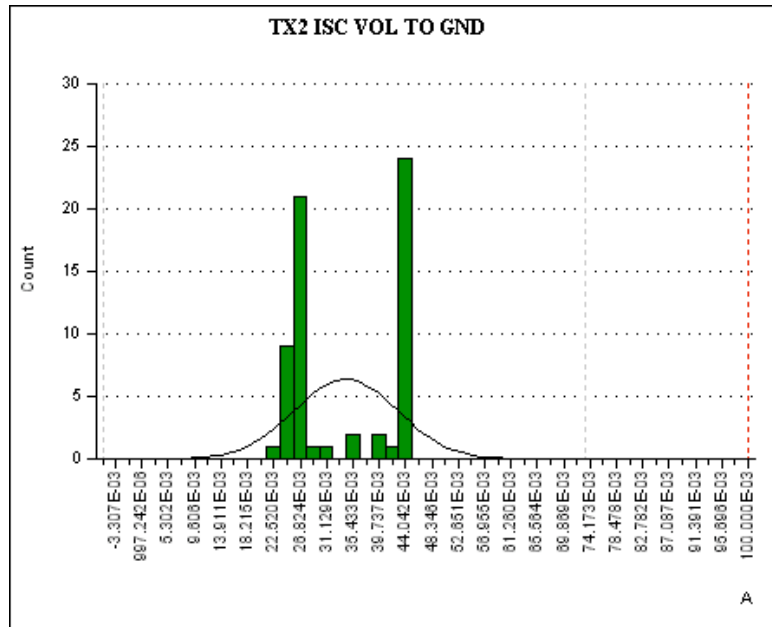
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=5.005, Test.Name=TX2 ISC VOL TO GND



Statistics: (A)

Max	43.842E-03	25%	26.111E-03	SpecHigh	100.000E-03
Mean	33.872E-03	10%	25.559E-03	SpecLow	N/A
Min	23.307E-03	N	62	PctWithinSpec	100.00
Range	20.535E-03	Cp	N/A	c	
StdDev	8.333E-03	Cpl	N/A	PctDefSpec	0
W	0.7436	Cpu	2.6453	NWithinSpec	62
WpValue	0.0000	Cpk	2.6453	NOutsideSpec	0
90%	43.476E-03	Skew	0.1609		
75%	43.235E-03	Kurtosis	-1.9361		
Median	27.845E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

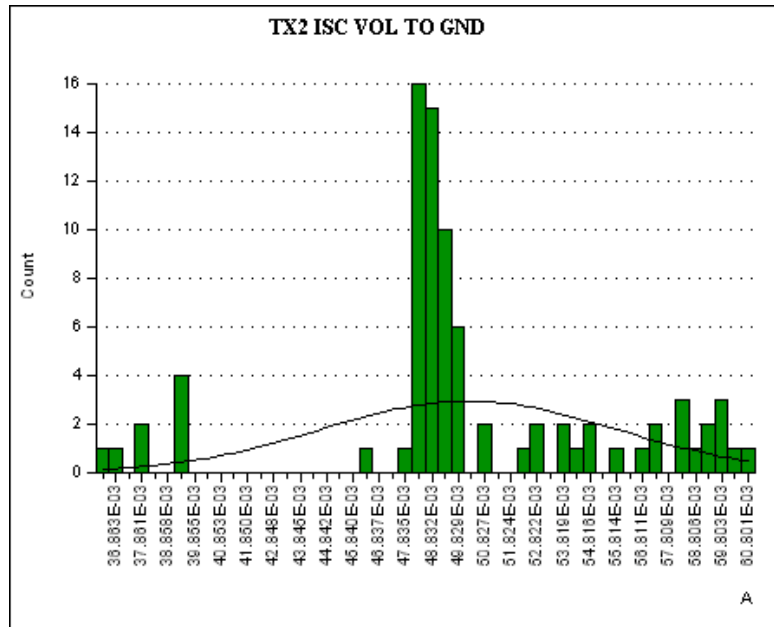
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
73.209E-03	-5.459E-03	100.00	0	62	0

Plot limits applied

NOutsidePlot

0

Test.Number=5.002, Test.Name=TX2 ISC VOL TO GND



Statistics: (A)

Max	60.801E-03	25%	48.453E-03	SpecHigh	N/A
Mean	50.102E-03	10%	46.379E-03	SpecLow	N/A
Min	36.365E-03	N	82	PctWithinSpec	N/A
Range	24.436E-03	Cp	N/A	PctDefSpec	N/A
StdDev	5.523E-03	Cpl	N/A	NWithinSpec	N/A
W	0.8719	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	58.422E-03	Skew	-0.2660		
75%	52.678E-03	Kurtosis	0.6457		
Median	49.086E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

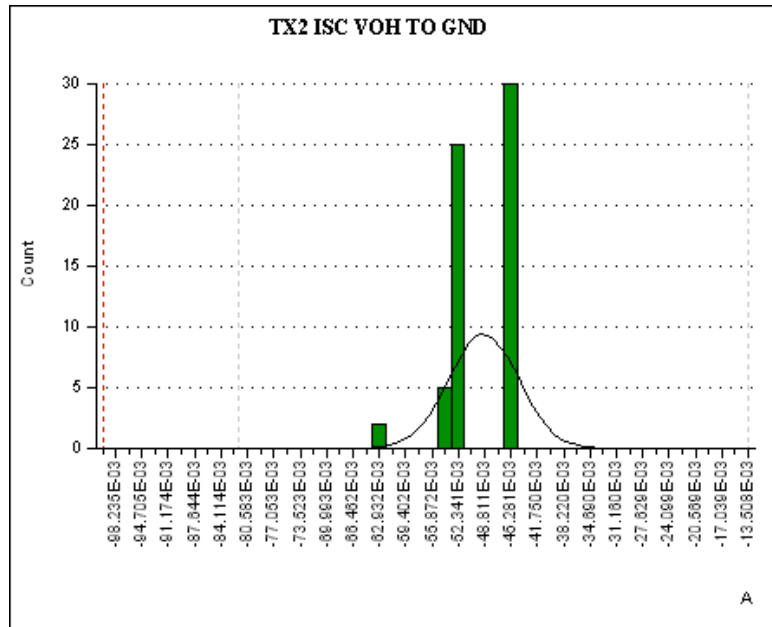
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=5.001, Test.Name=TX2 ISC VOH TO GND



Statistics: (A)

Max	-44.568E-03	25%	-53.057E-03	SpecHigh	N/A
Mean	-49.494E-03	10%	-53.233E-03	SpecLow	-100.000E-03
Min	-63.455E-03	N	62	PctWithinSpec	100.00
Range	18.887E-03	Cp	N/A	PctDefSpec	0
StdDev	4.646E-03	Cpl	3.6238	NWithinSpec	62
W	0.7556	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	3.6238		
90%	-44.861E-03	Skew	-0.5991		
75%	-45.085E-03	Kurtosis	-0.0081		
Median	-52.468E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

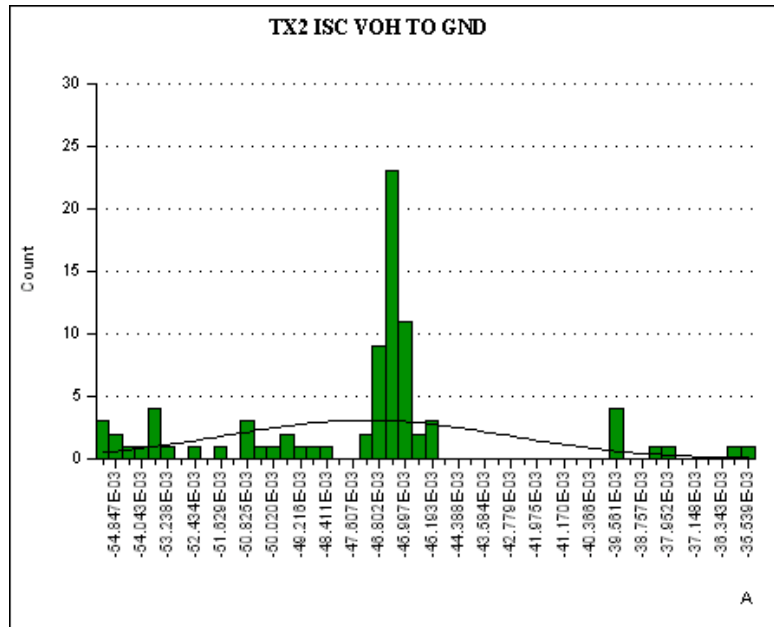
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
-13.508E-03	-81.745E-03	100.00	0	62	0

Plot limits applied

NOutsidePlot

0

Test.Number=5.003, Test.Name=TX2 ISC VOH TO GND



Statistics: (A)

Max	-35.539E-03	25%	-49.517E-03	SpecHigh	N/A
Mean	-47.266E-03	10%	-53.645E-03	SpecLow	N/A
Min	-55.250E-03	N	82	PctWithinSpec	N/A
Range	19.711E-03	Cp	N/A	c	
StdDev	4.224E-03	Cpl	N/A	PctDefSpec	N/A
W	0.8703	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	-45.201E-03	Skew	0.2800		
75%	-46.105E-03	Kurtosis	0.8879		
Median	-46.488E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

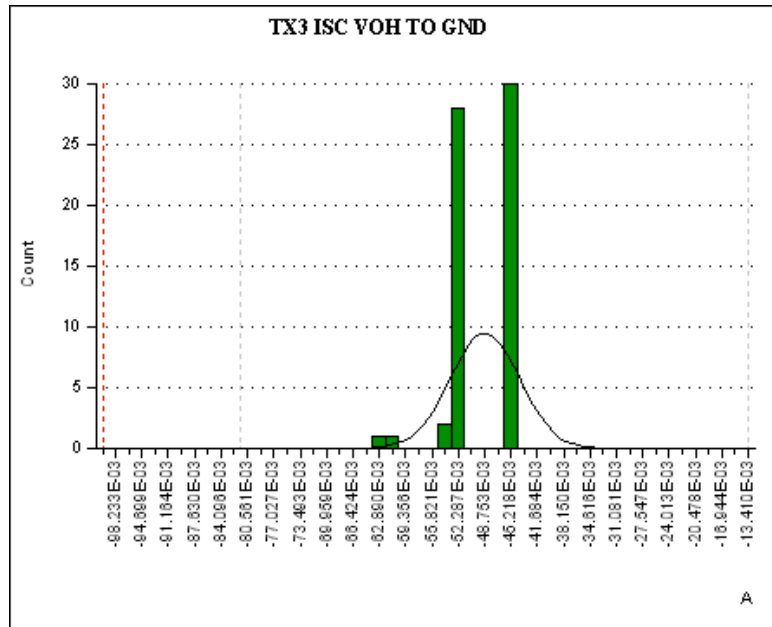
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=5.002, Test.Name=TX3 ISC VOH TO GND



Statistics: (A)

Max	-44.413E-03	25%	-52.843E-03	SpecHigh	N/A
Mean	-49.305E-03	10%	-53.108E-03	SpecLow	-100.000E-03
Min	-63.142E-03	N	62	PctWithinSpec	100.00
Range	18.729E-03	Cp	N/A	PctDefSpec	0
StdDev	4.593E-03	Cpl	3.6791	NWithinSpec	62
W	0.7547	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	3.6791		
90%	-44.728E-03	Skew	-0.5980		
75%	-44.976E-03	Kurtosis	-0.0109		
Median	-52.315E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

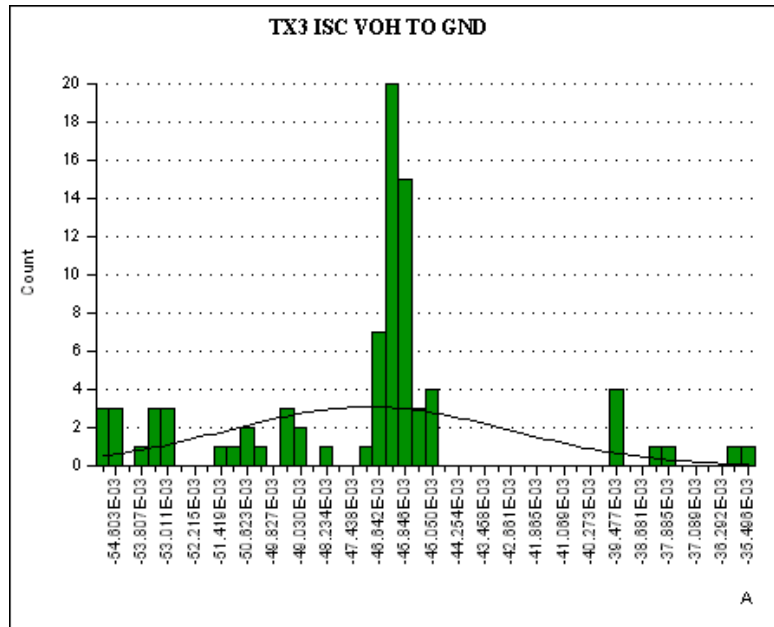
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
-13.410E-03	-81.501E-03	100.00	0	62	0

Plot limits applied

NOutsidePlot

0

Test.Number=5.004, Test.Name=TX3 ISC VOH TO GND



Statistics: (A)

Max	-35.496E-03	25%	-49.257E-03	SpecHigh	N/A
Mean	-47.026E-03	10%	-53.363E-03	SpecLow	N/A
Min	-55.001E-03	N	82	PctWithinSpec	N/A
Range	19.505E-03	Cp	N/A	c	
StdDev	4.210E-03	Cpl	N/A	PctDefSpec	N/A
W	0.8703	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	-44.925E-03	Skew	0.2161		
75%	-45.785E-03	Kurtosis	0.7916		
Median	-46.158E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

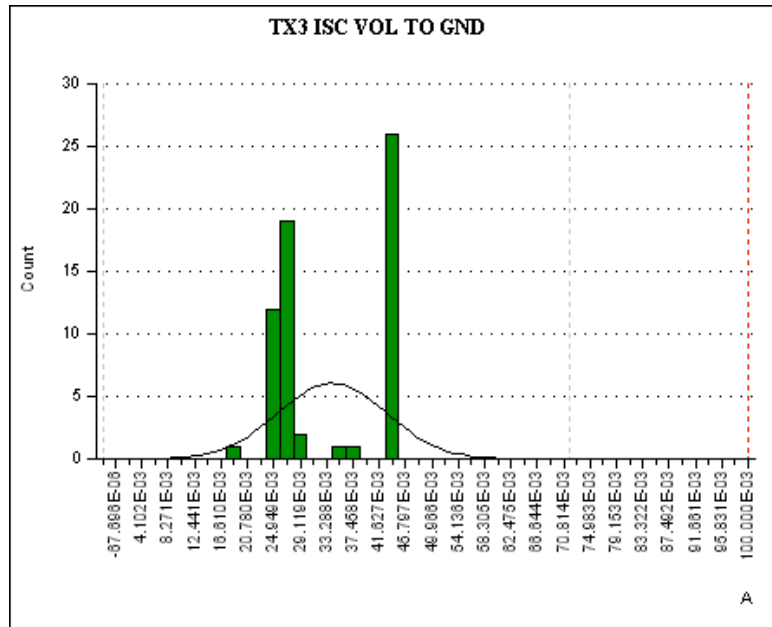
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=5.006, Test.Name=TX3 ISC VOL TO GND



Statistics: (A)

Max	43.941E-03	25%	26.013E-03	SpecHigh	100.000E-03
Mean	33.797E-03	10%	25.760E-03	SpecLow	N/A
Min	18.256E-03	N	62	PctWithinSpec	100.00
Range	25.685E-03	Cp	N/A	c	
StdDev	8.515E-03	Cpl	N/A	PctDefSpec	0
W	0.7474	Cpu	2.5916	NWithinSpec	62
WpValue	0.0000	Cpk	2.5916	NOutsideSpec	0
90%	43.508E-03	Skew	0.1536		
75%	43.295E-03	Kurtosis	-1.8459		
Median	27.953E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

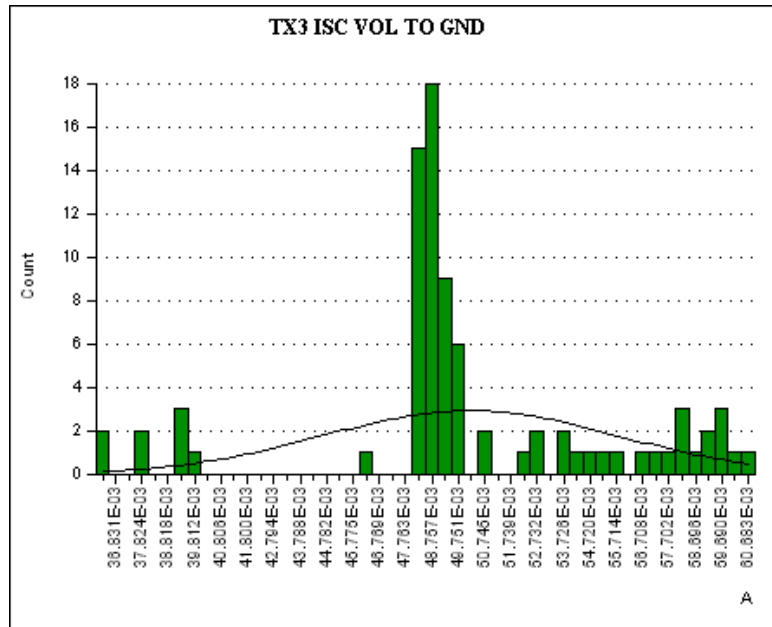
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
71.642E-03	-2.152E-03	100.00	0	62	0

Plot limits applied

NOutsidePlot

0

Test.Number=5.005, Test.Name=TX3 ISC VOL TO GND



Statistics: (A)

Max	60.683E-03	25%	48.387E-03	SpecHigh	N/A
Mean	50.064E-03	10%	46.392E-03	SpecLow	N/A
Min	36.334E-03	N	82	PctWithinSpec	N/A
Range	24.350E-03	Cp	N/A	PctDefSpec	N/A
StdDev	5.522E-03	Cpl	N/A	NWithinSpec	N/A
W	0.8716	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	58.383E-03	Skew	-0.2471		
75%	52.640E-03	Kurtosis	0.6190		
Median	48.948E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

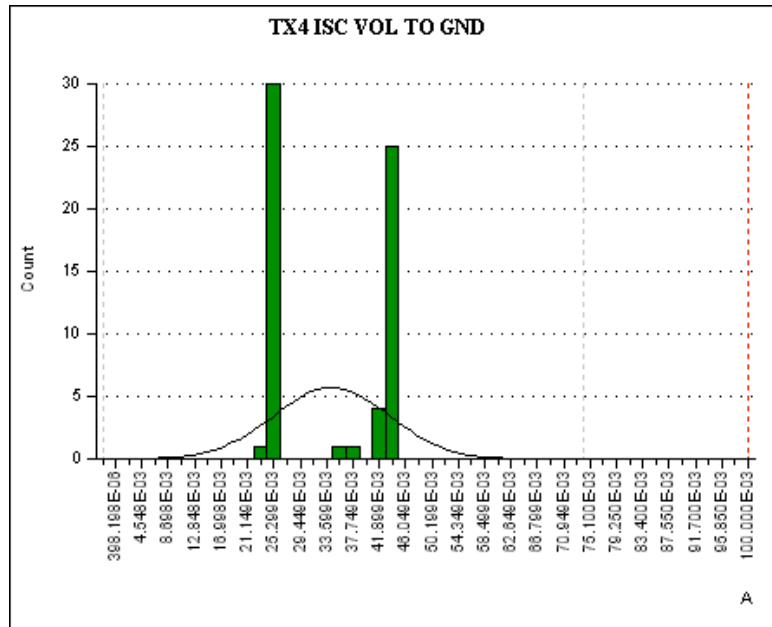
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=5.007, Test.Name=TX4 ISC VOL TO GND



Statistics: (A)

Max	43.840E-03	25%	25.216E-03	SpecHigh	100.000E-03
Mean	34.014E-03	10%	24.754E-03	SpecLow	N/A
Min	23.873E-03	N	62	PctWithinSpec	100.00
Range	19.967E-03	Cp	N/A	PctDefSpec	0
StdDev	8.971E-03	Cpl	N/A	NWithinSpec	62
W	0.6958	Cpu	2.4519	NOutsideSpec	0
WpValue	0.0000	Cpk	2.4519		
90%	43.521E-03	Skew	0.0380		
75%	43.299E-03	Kurtosis	-2.0245		
Median	31.295E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

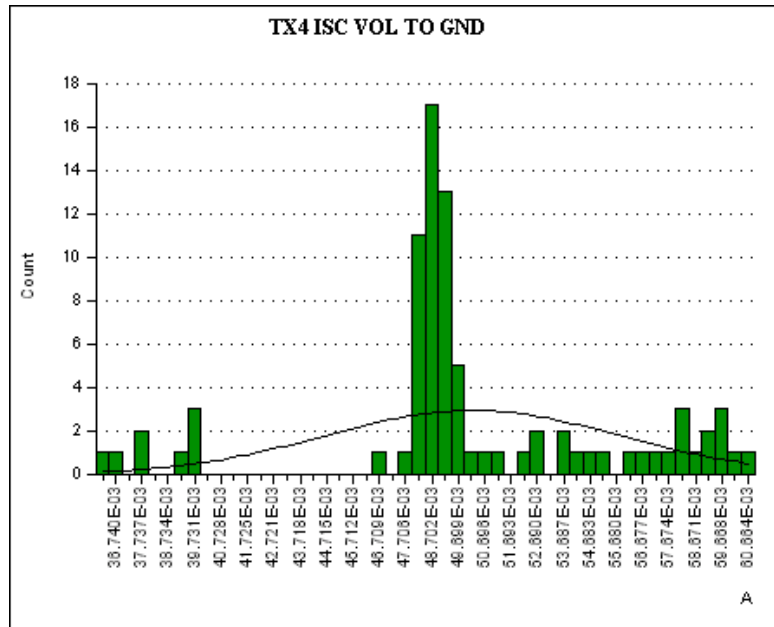
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
73.968E-03	-1.677E-03	100.00	0	62	0

Plot limits applied

NOutsidePlot

0

Test.Number=5.006, Test.Name=TX4 ISC VOL TO GND



Statistics: (A)

Max	60.664E-03	25%	48.417E-03	SpecHigh	N/A
Mean	50.103E-03	10%	46.474E-03	SpecLow	N/A
Min	36.242E-03	N	82	PctWithinSpec	N/A
Range	24.422E-03	Cp	N/A	c	
StdDev	5.512E-03	Cpl	N/A	PctDefSpec	N/A
W	0.8741	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	58.412E-03	Skew	-0.2592		
75%	52.653E-03	Kurtosis	0.6511		
Median	49.063E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T		0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T		0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T		0

Data: Raw Data

Stat limits applied

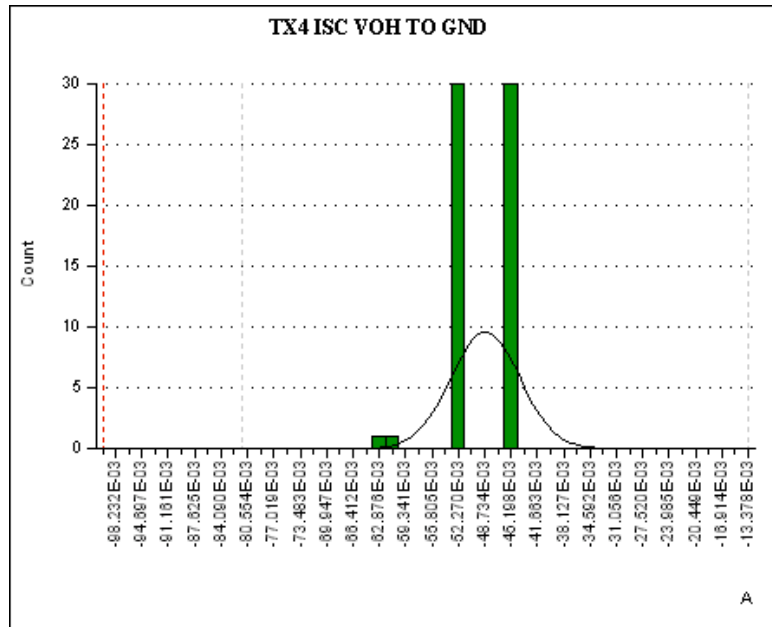
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=5.003, Test.Name=TX4 ISC VOH TO GND



Statistics: (A)

Max	-44.385E-03	25%	-52.705E-03	SpecHigh	N/A
Mean	-49.217E-03	10%	-52.986E-03	SpecLow	-100.000E-03
Min	-62.999E-03	N	62	PctWithinSpec	100.00
Range	18.613E-03	Cp	N/A	c	
StdDev	4.566E-03	Cpl	3.7069	PctDefSpec	0
W	0.7578	Cpu	N/A	NWithinSpec	62
WpValue	0.0000	Cpk	3.7069	NOutsideSpec	0
90%	-44.690E-03	Skew	-0.6014		
75%	-44.894E-03	Kurtosis	0.0034		
Median	-52.119E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

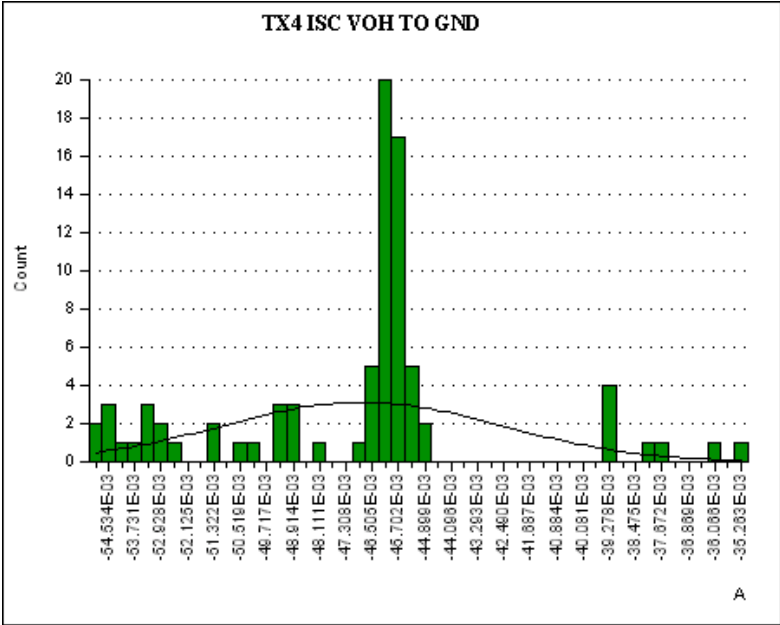
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
-13.378E-03	-81.390E-03	100.00	0	62	0

Plot limits applied

NOutsidePlot

0

Test.Number=5.007, Test.Name=TX4 ISC VOH TO GND



Statistics: (A)

Max	-35.263E-03	25%	-48.993E-03	SpecHigh	N/A
Mean	-46.885E-03	10%	-53.192E-03	SpecLow	N/A
Min	-54.936E-03	N	82	PctWithinSpec	N/A
Range	19.673E-03	Cp	N/A	c	
StdDev	4.202E-03	Cpl	N/A	PctDefSpec	N/A
W	0.8701	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	-44.955E-03	Skew	0.2221		
75%	-45.704E-03	Kurtosis	0.8315		
Median	-46.032E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

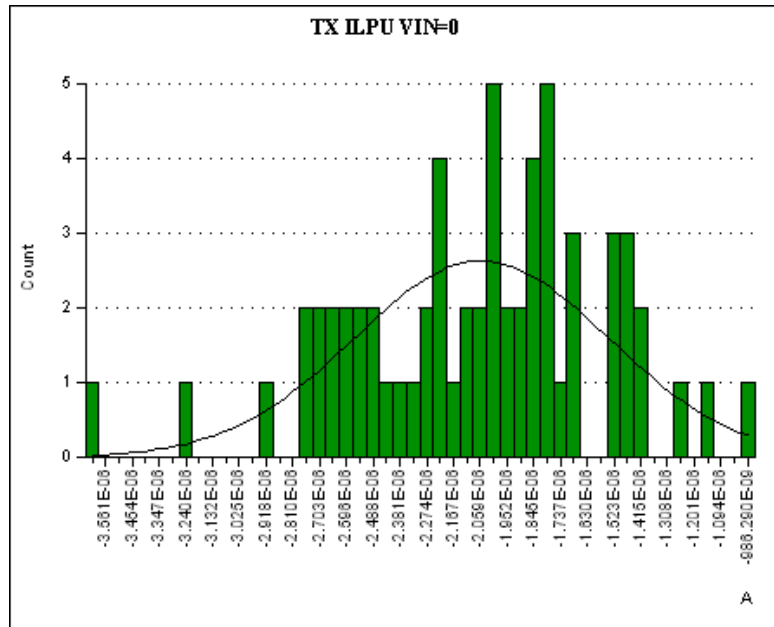
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=6.000, Test.Name=TX ILPU VIN=0



Statistics: (A)

Max	-986.290E-09	25%	-2.429E-06	SpecHigh	N/A
Mean	-2.072E-06	10%	-2.696E-06	SpecLow	N/A
Min	-3.615E-06	N	62	PctWithinSpec	N/A
Range	2.629E-06	Cp	N/A	c	
StdDev	504.635E-09	Cpl	N/A	PctDefSpec	N/A
W	0.9835	Cpu	N/A	NWithinSpec	N/A
WpValue	0.5689	Cpk	N/A	NOutsideSpec	N/A
90%	-1.466E-06	Skew	-0.4592		
75%	-1.765E-06	Kurtosis	0.5375		
Median	-2.018E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

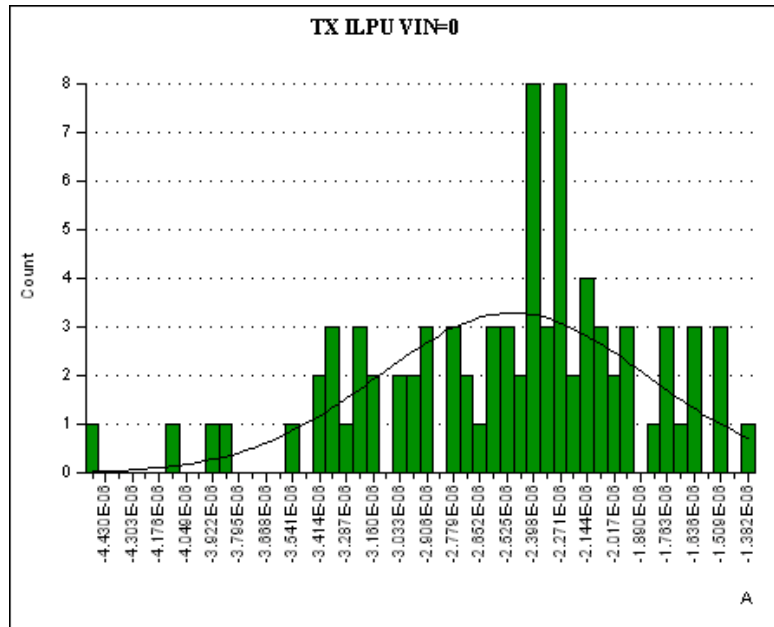
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=6.000, Test.Name=TX ILPU VIN=0



Statistics: (A)

Max	-1.382E-06	25%	-2.925E-06	SpecHigh	N/A
Mean	-2.519E-06	10%	-3.336E-06	SpecLow	N/A
Min	-4.493E-06	N	82	PctWithinSpec	N/A
Range	3.111E-06	Cp	N/A	c	
StdDev	632.275E-09	Cpl	N/A	PctDefSpec	N/A
W	0.9642	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0219	Cpk	N/A	NOutsideSpec	N/A
90%	-1.733E-06	Skew	-0.6885		
75%	-2.118E-06	Kurtosis	0.4721		
Median	-2.397E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

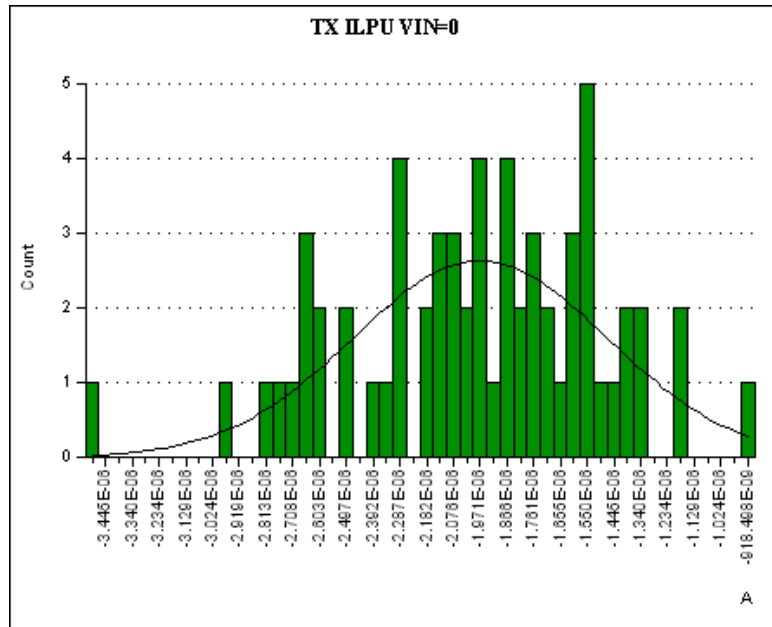
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=6.001, Test.Name=TX ILPU VIN=0



Statistics: (A)

Max	-918.498E-09	25%	-2.290E-06	SpecHigh	N/A
Mean	-1.989E-06	10%	-2.635E-06	SpecLow	N/A
Min	-3.497E-06	N	62	PctWithinSpec	N/A
Range	2.579E-06	Cp	N/A	c	
StdDev	494.394E-09	Cpl	N/A	PctDefSpec	N/A
W	0.9829	Cpu	N/A	NWithinSpec	N/A
WpValue	0.5405	Cpk	N/A	NOutsideSpec	N/A
90%	-1.392E-06	Skew	-0.4777		
75%	-1.626E-06	Kurtosis	0.3256		
Median	-1.956E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

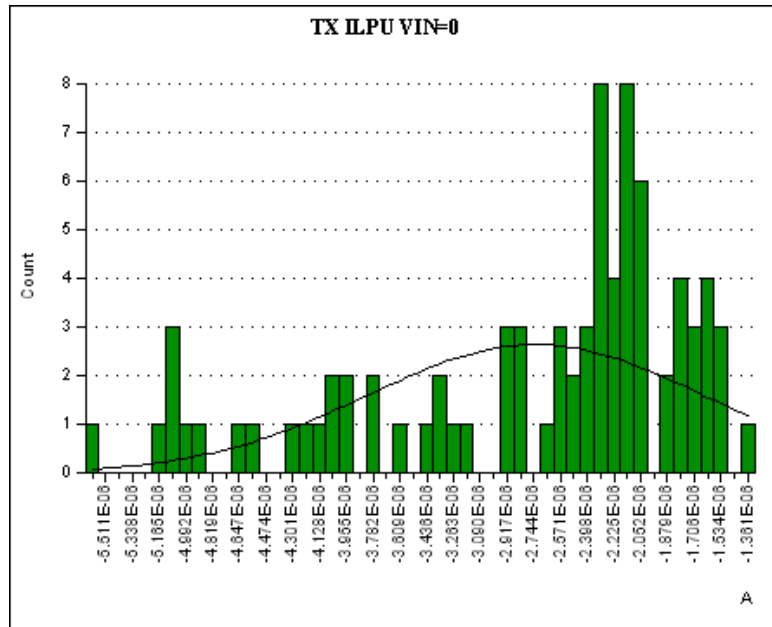
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=6.001, Test.Name=TX ILPU VIN=0



Statistics: (A)

Max	-1.361E-06	25%	-3.350E-06	SpecHigh	N/A
Mean	-2.761E-06	10%	-4.518E-06	SpecLow	N/A
Min	-5.598E-06	N	82	PctWithinSpec	N/A
Range	4.237E-06	Cp	N/A	c	
StdDev	1.071E-06	Cpl	N/A	PctDefSpec	N/A
W	0.8766	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	-1.708E-06	Skew	-1.0145		
75%	-2.059E-06	Kurtosis	-0.0185		
Median	-2.326E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

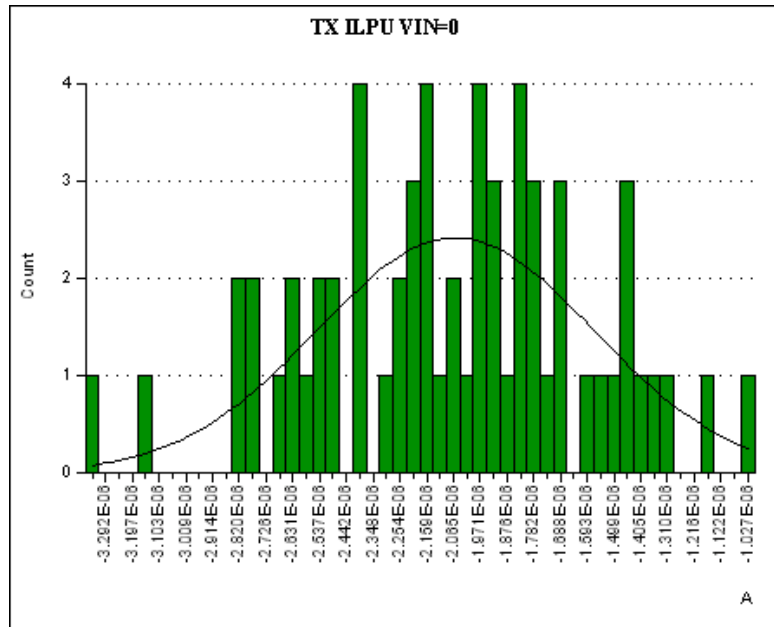
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=6.002, Test.Name=TX ILPU VIN=0



Statistics: (A)

Max	-1.027E-06	25%	-2.390E-06	SpecHigh	N/A
Mean	-2.073E-06	10%	-2.675E-06	SpecLow	N/A
Min	-3.339E-06	N	62	PctWithinSpec	N/A
Range	2.311E-06	Cp	N/A	c	
StdDev	482.293E-09	Cpl	N/A	PctDefSpec	N/A
W	0.9920	Cpu	N/A	NWithinSpec	N/A
WpValue	0.9600	Cpk	N/A	NOutsideSpec	N/A
90%	-1.458E-06	Skew	-0.2387		
75%	-1.764E-06	Kurtosis	-0.1006		
Median	-2.035E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01.AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01.AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01.AT	-	0

Data: Raw Data

Stat limits applied

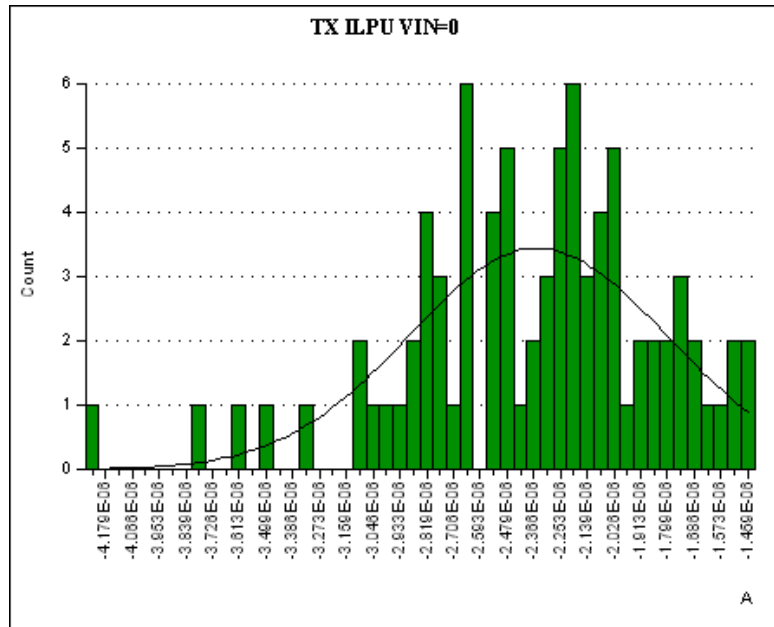
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=6.002, Test.Name=TX ILPU VIN=0



Statistics: (A)

Max	-1.459E-06	25%	-2.674E-06	SpecHigh	N/A
Mean	-2.370E-06	10%	-2.976E-06	SpecLow	N/A
Min	-4.236E-06	N	82	PctWithinSpec	N/A
Range	2.777E-06	Cp	N/A	c	
StdDev	538.625E-09	Cpl	N/A	PctDefSpec	N/A
W	0.9616	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0150	Cpk	N/A	NOutsideSpec	N/A
90%	-1.718E-06	Skew	-0.7796		
75%	-2.025E-06	Kurtosis	1.1343		
Median	-2.277E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

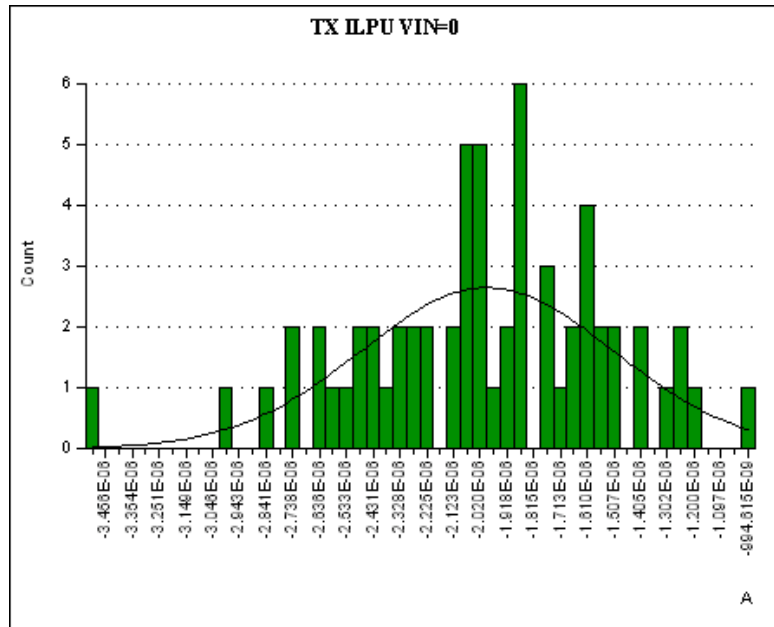
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=6.003, Test.Name=TX ILPU VIN=0



Statistics: (A)

Max	-994.615E-09	25%	-2.315E-06	SpecHigh	N/A
Mean	-2.009E-06	10%	-2.644E-06	SpecLow	N/A
Min	-3.508E-06	N	62	PctWithinSpec	N/A
Range	2.513E-06	Cp	N/A	PctDefSpec	N/A
StdDev	478.778E-09	Cpl	N/A	NWithinSpec	N/A
W	0.9843	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.6137	Cpk	N/A		
90%	-1.430E-06	Skew	-0.4685		
75%	-1.637E-06	Kurtosis	0.5231		
Median	-2.009E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

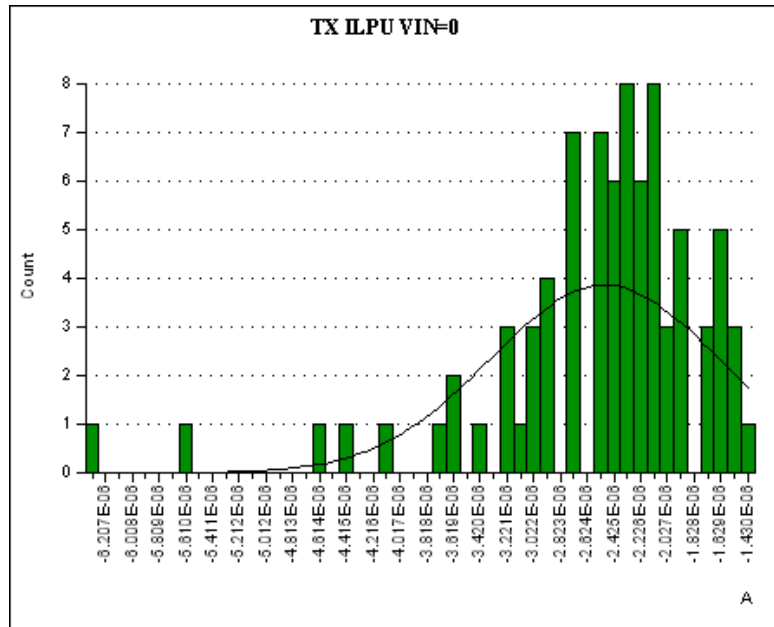
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=6.003, Test.Name=TX ILPU VIN=0



Statistics: (A)

Max	-1.430E-06	25%	-2.759E-06	SpecHigh	N/A
Mean	-2.536E-06	10%	-3.386E-06	SpecLow	N/A
Min	-6.306E-06	N	82	PctWithinSpec	N/A
Range	4.877E-06	Cp	N/A	c	
StdDev	843.942E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8299	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	-1.670E-06	Skew	-2.0580		
75%	-2.082E-06	Kurtosis	6.0560		
Median	-2.369E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

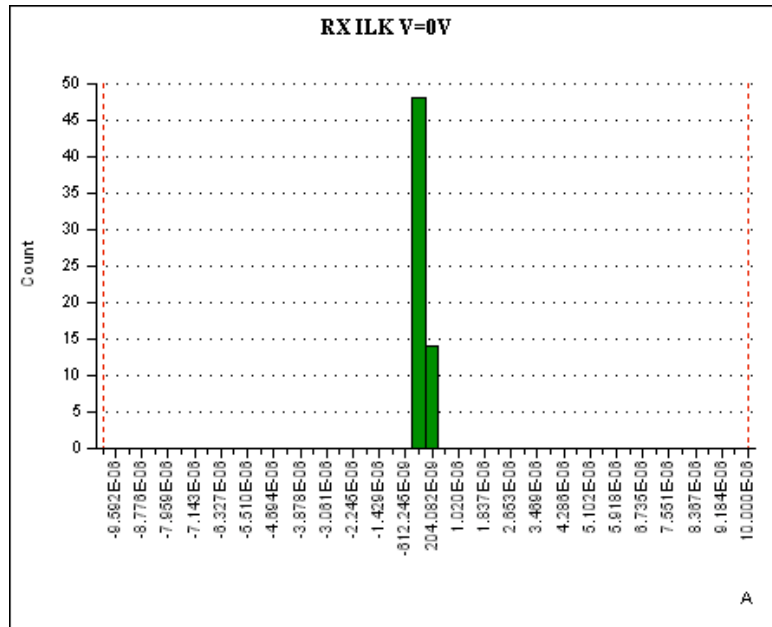
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=7.000, Test.Name=RX ILK V=0V



Statistics: (A)

Max	37.723E-09	25%	-15.992E-09	SpecHigh	10.000E-06
Mean	-8.623E-09	10%	-21.443E-09	SpecLow	-10.000E-06
Min	-85.218E-09	N	62	PctWithinSpec	100.00
Range	122.940E-09	Cp	>4.0000	PctDefSpec	0
StdDev	14.961E-09	Cpl	>4.0000	NWithinSpec	62
W	0.8218	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	4.347E-09	Skew	-1.7369		
75%	-466.567E-12	Kurtosis	11.3833		
Median	-7.207E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

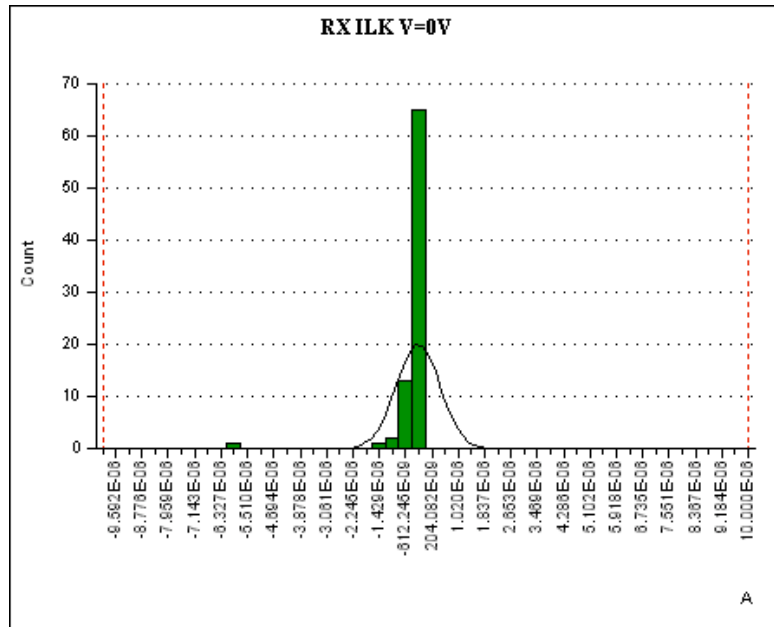
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.000, Test.Name=RX ILK V=0V



Statistics: (A)

Max	-54.741E-09	25%	-191.349E-09	SpecHigh	10.000E-06
Mean	-334.593E-09	10%	-642.130E-09	SpecLow	-10.000E-06
Min	-5.806E-06	N	82	PctWithinSpec	100.00
Range	5.751E-06	Cp	>4.0000	c	
StdDev	660.706E-09	Cpl	>4.0000	PctDefSpec	0
W	0.2916	Cpu	>4.0000	NWithinSpec	82
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	-149.647E-09	Skew	-7.2952		
75%	-159.299E-09	Kurtosis	59.6268		
Median	-166.336E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

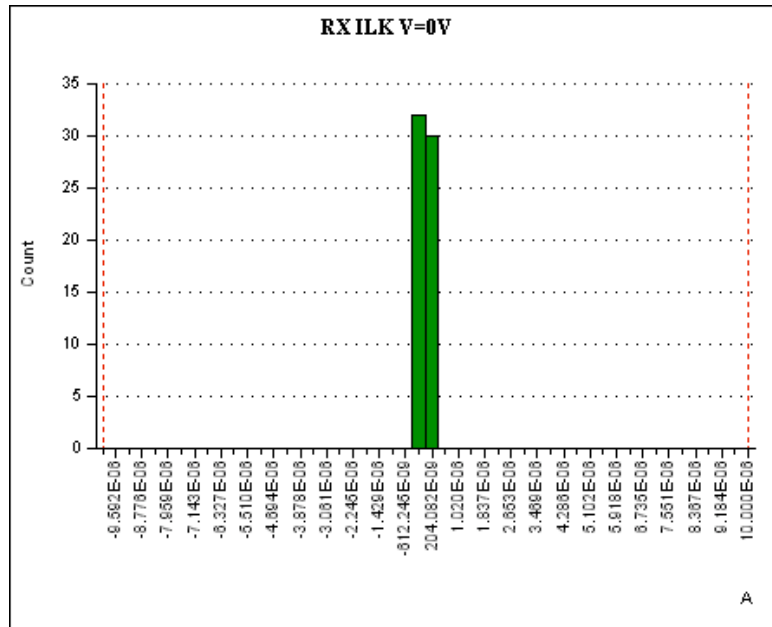
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.001, Test.Name=RX ILK V=0V



Statistics: (A)

Max	20.998E-09	25%	-16.139E-09	SpecHigh	10.000E-06
Mean	-4.857E-09	10%	-21.664E-09	SpecLow	-10.000E-06
Min	-93.157E-09	N	62	PctWithinSpec	100.00
Range	114.155E-09	Cp	>4.0000	PctDefSpec	0
StdDev	17.536E-09	Cpl	>4.0000	NWithinSpec	62
W	0.8173	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	12.876E-09	Skew	-2.0509		
75%	9.043E-09	Kurtosis	9.0556		
Median	-1.019E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

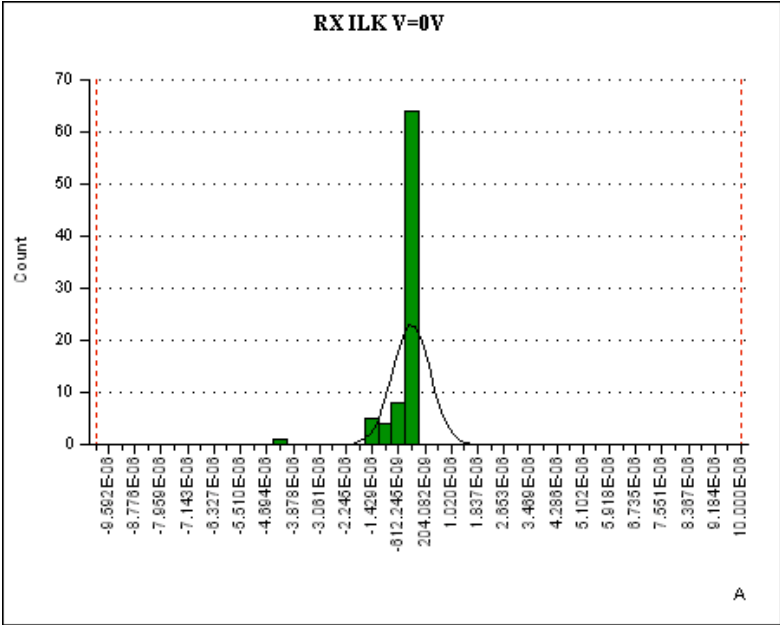
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.001, Test.Name=RX ILK V=0V



Statistics: (A)

Max	-28.366E-09	25%	-215.739E-09	SpecHigh	10.000E-06
Mean	-325.359E-09	10%	-1.062E-06	SpecLow	-10.000E-06
Min	-4.124E-06	N	82	PctWithinSpec	100.00
Range	4.096E-06	Cp	>4.0000	PctDefSpec	0
StdDev	574.737E-09	Cpl	>4.0000	NWithinSpec	82
W	0.4941	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	-78.323E-09	Skew	-4.1762		
75%	-92.322E-09	Kurtosis	23.3844		
Median	-98.658E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

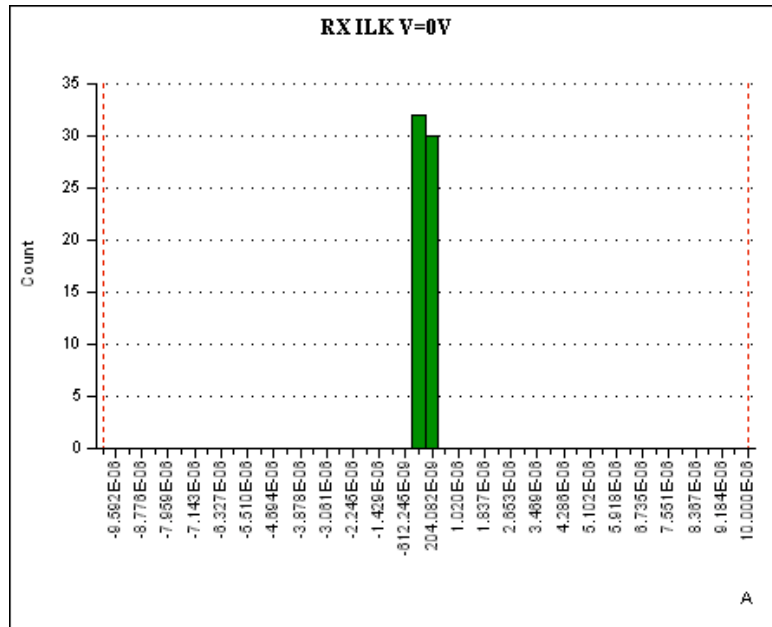
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=7.002, Test.Name=RX ILK V=0V



Statistics: (A)

Max	19.654E-09	25%	-36.989E-09	SpecHigh	10.000E-06
Mean	-13.519E-09	10%	-47.304E-09	SpecLow	-10.000E-06
Min	-118.820E-09	N	62	PctWithinSpec	100.00
Range	138.474E-09	Cp	>4.0000	c	
StdDev	29.300E-09	Cpl	>4.0000	PctDefSpec	0
W	0.8680	Cpu	>4.0000	NWithinSpec	62
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	14.351E-09	Skew	-1.0156		
75%	11.697E-09	Kurtosis	1.1882		
Median	-12.786E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

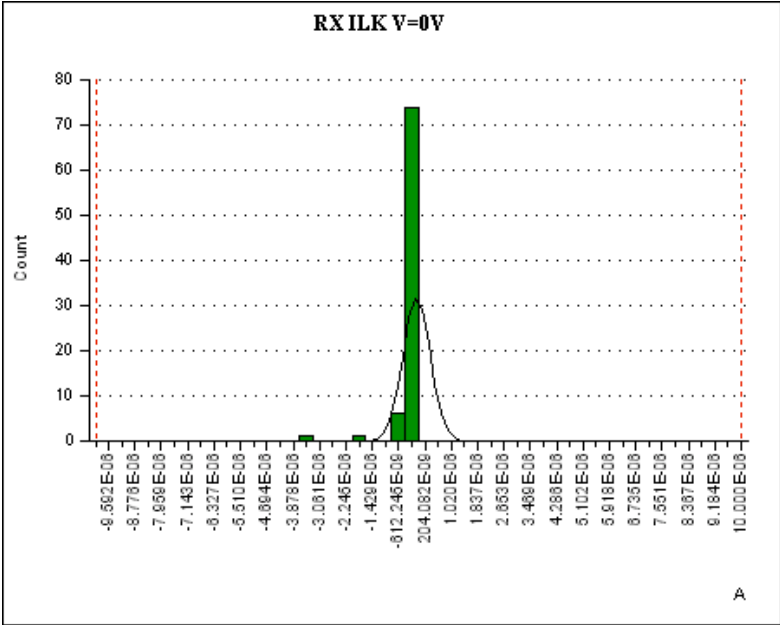
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.002, Test.Name=RX ILK V=0V



Statistics: (A)

Max	-7.293E-09	25%	-59.682E-09	SpecHigh	10.000E-06
Mean	-166.142E-09	10%	-383.287E-09	SpecLow	-10.000E-06
Min	-3.321E-06	N	82	PctWithinSpec	100.00
Range	3.313E-06	Cp	>4.0000	c	
StdDev	421.431E-09	Cpl	>4.0000	PctDefSpec	0
W	0.3317	Cpu	>4.0000	NWithinSpec	82
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	-32.417E-09	Skew	-6.0019		
75%	-42.438E-09	Kurtosis	41.2656		
Median	-50.875E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

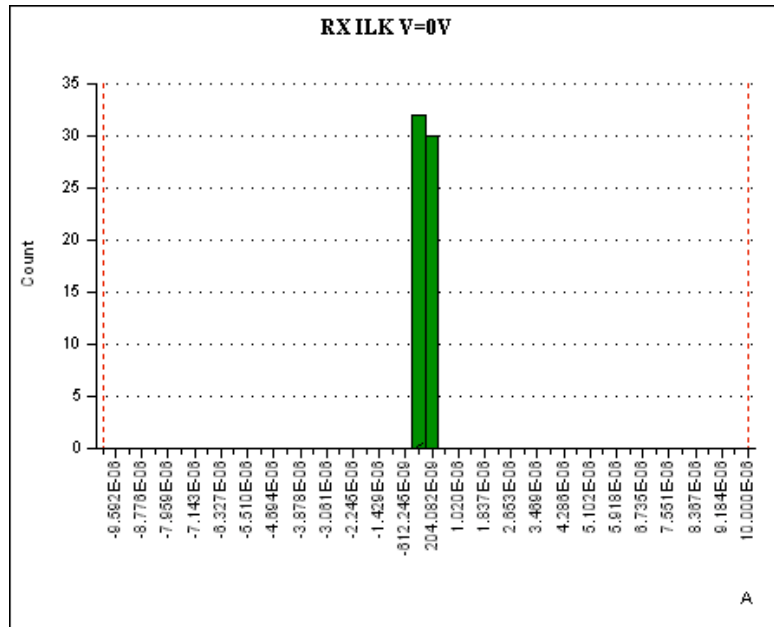
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=7.003, Test.Name=RX ILK V=0V



Statistics: (A)

Max	24.958E-09	25%	-44.430E-09	SpecHigh	10.000E-06
Mean	-20.869E-09	10%	-73.829E-09	SpecLow	-10.000E-06
Min	-312.281E-09	N	62	PctWithinSpec	100.00
Range	337.238E-09	Cp	>4.0000	PctDefSpec	0
StdDev	52.013E-09	Cpl	>4.0000	NWithinSpec	62
W	0.7070	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	18.180E-09	Skew	-3.1105		
75%	14.277E-09	Kurtosis	15.2165		
Median	-6.337E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

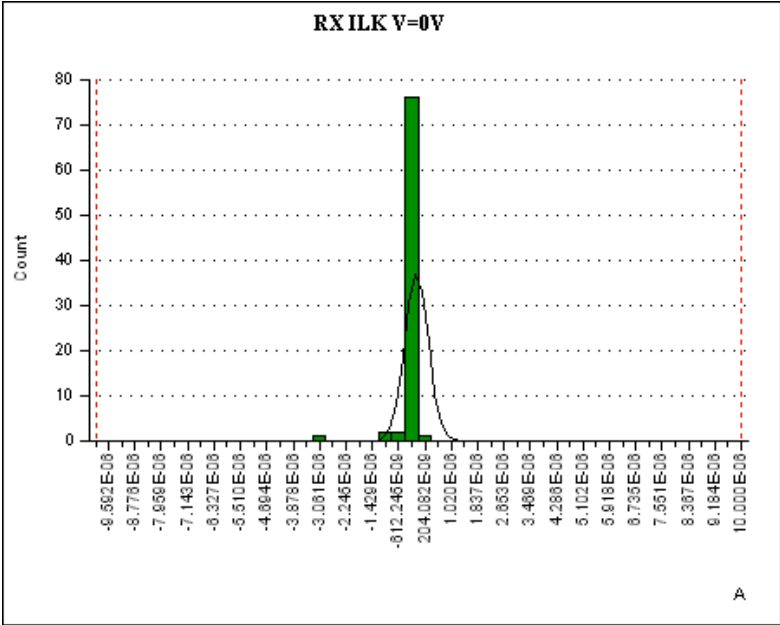
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.003, Test.Name=RX ILK V=0V



Statistics: (A)

Max	7.737E-09	25%	-109.710E-09	SpecHigh	10.000E-06
Mean	-171.720E-09	10%	-215.002E-09	SpecLow	-10.000E-06
Min	-3.115E-06	N	82	PctWithinSpec	100.00
Range	3.123E-06	Cp	>4.0000	PctDefSpec	0
StdDev	361.391E-09	Cpl	>4.0000	NWithinSpec	82
W	0.2873	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	-43.470E-09	Skew	-7.0494		
75%	-90.776E-09	Kurtosis	55.8440		
Median	-101.200E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

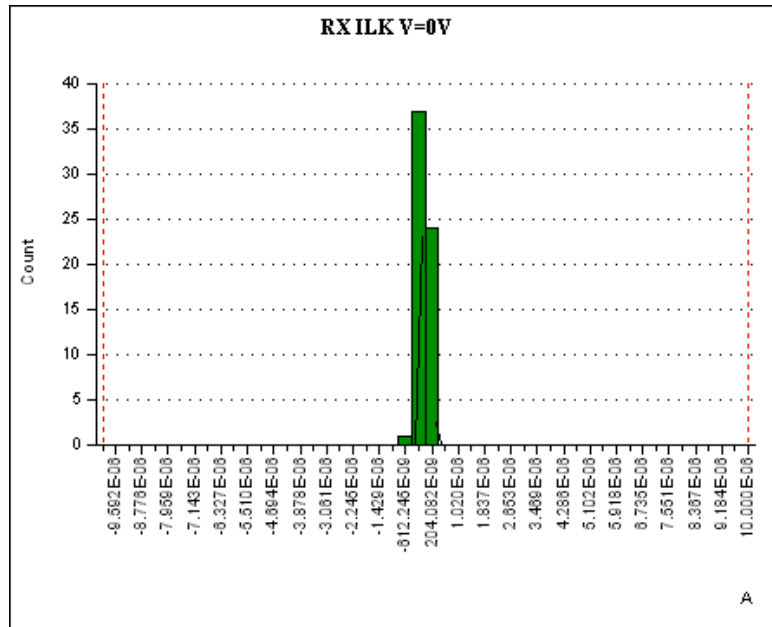
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=7.004, Test.Name=RX ILK V=0V



Statistics: (A)

Max	16.931E-09	25%	-78.177E-09	SpecHigh	10.000E-06
Mean	-42.536E-09	10%	-106.028E-09	SpecLow	-10.000E-06
Min	-608.733E-09	N	62	PctWithinSpec	100.00
Range	625.664E-09	Cp	>4.0000	PctDefSpec	0
StdDev	87.781E-09	Cpl	>4.0000	NWithinSpec	62
W	0.5608	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	10.517E-09	Skew	-4.6082		
75%	7.053E-09	Kurtosis	28.3792		
Median	-19.198E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

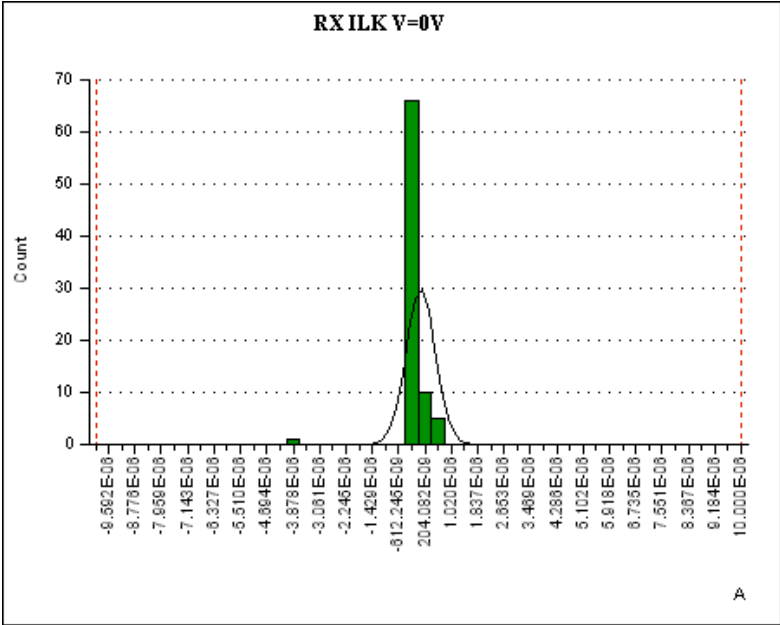
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.004, Test.Name=RX ILK V=0V



Statistics: (A)

Max	640.890E-09	25%	-67.050E-09	SpecHigh	10.000E-06
Mean	-43.036E-09	10%	-74.051E-09	SpecLow	-10.000E-06
Min	-3.762E-06	N	82	PctWithinSpec	100.00
Range	4.403E-06	Cp	>4.0000	c	
StdDev	448.078E-09	Cpl	>4.0000	PctDefSpec	0
W	0.2964	Cpu	>4.0000	NWithinSpec	82
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	279.400E-09	Skew	-7.0620		
75%	-36.324E-09	Kurtosis	60.2058		
Median	-58.648E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

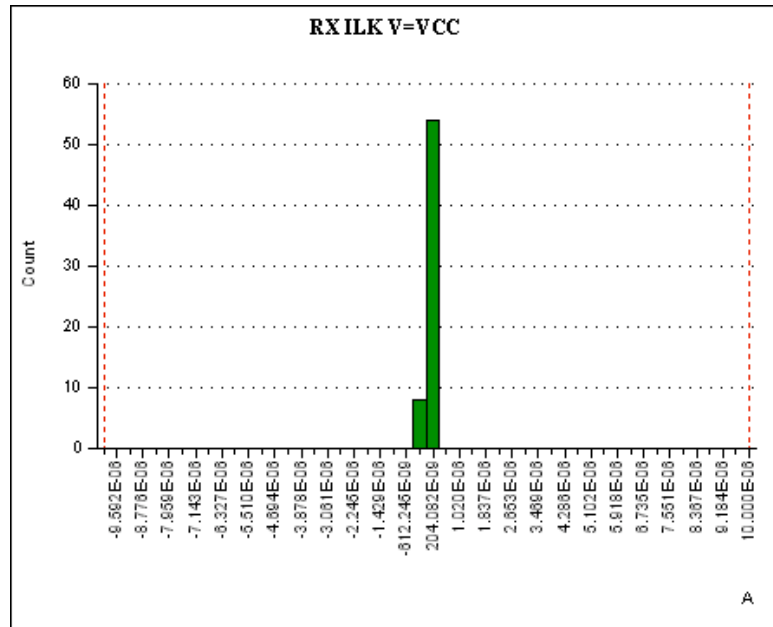
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=7.005, Test.Name=RX ILK V=VCC



Statistics: (A)

Max	75.670E-09	25%	10.886E-09	SpecHigh	10.000E-06
Mean	19.103E-09	10%	-4.866E-09	SpecLow	-10.000E-06
Min	-15.918E-09	N	62	PctWithinSpec	100.00
Range	91.589E-09	Cp	>4.0000	PctDefSpec	0
StdDev	17.755E-09	Cpl	>4.0000	NWithinSpec	62
W	0.9582	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0335	Cpk	>4.0000		
90%	38.902E-09	Skew	0.5348		
75%	29.544E-09	Kurtosis	1.2994		
Median	18.620E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

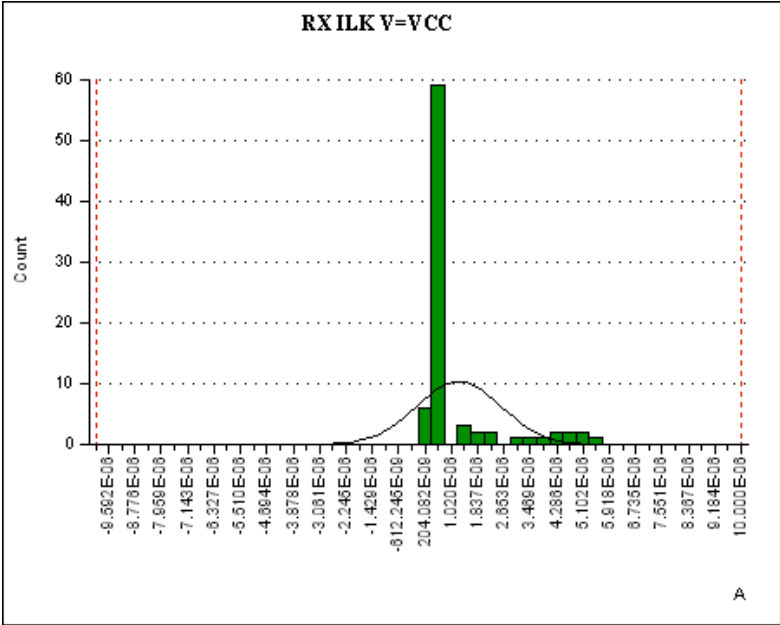
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.005, Test.Name=RX ILK V=VCC



Statistics: (A)

Max	5.515E-06	25%	567.722E-09	SpecHigh	10.000E-06
Mean	1.129E-06	10%	537.512E-09	SpecLow	-10.000E-06
Min	168.733E-09	N	82	PctWithinSpec	100.00
Range	5.346E-06	Cp	2.5953	PctDefSpec	0
StdDev	1.284E-06	Cpl	2.8882	NWithinSpec	82
W	0.5625	Cpu	2.3024	NOutsideSpec	0
WpValue	0.0000	Cpk	2.3024		
90%	3.410E-06	Skew	2.2635		
75%	716.709E-09	Kurtosis	3.8734		
Median	607.436E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T		0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T		0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T		0

Data: Raw Data

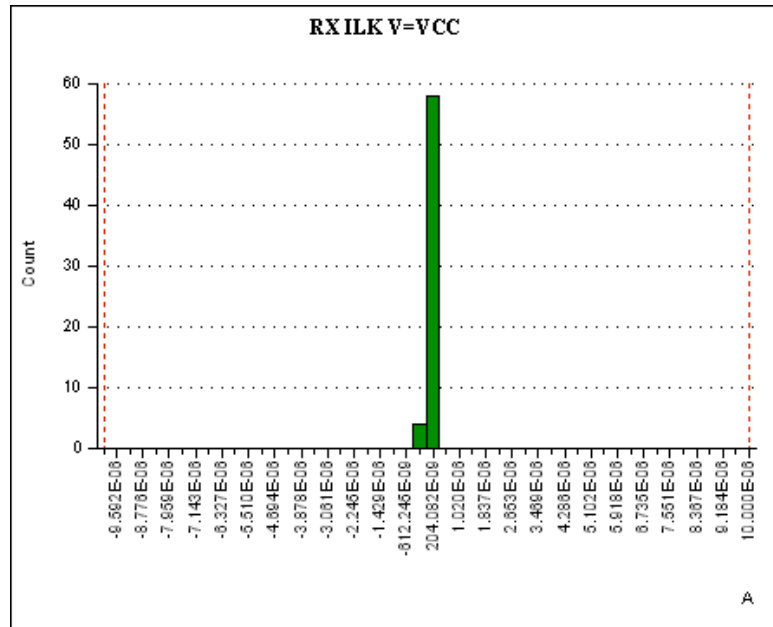
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=7.006, Test.Name=RX ILK V=VCC



Statistics: (A)

Max	136.526E-09	25%	17.074E-09	SpecHigh	10.000E-06
Mean	31.739E-09	10%	9.928E-09	SpecLow	-10.000E-06
Min	-9.506E-09	N	62	PctWithinSpec	100.00
Range	146.032E-09	Cp	>4.0000	PctDefSpec	0
StdDev	27.285E-09	Cpl	>4.0000	NWithinSpec	62
W	0.8294	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	70.880E-09	Skew	1.7700		
75%	35.659E-09	Kurtosis	3.8365		
Median	23.708E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

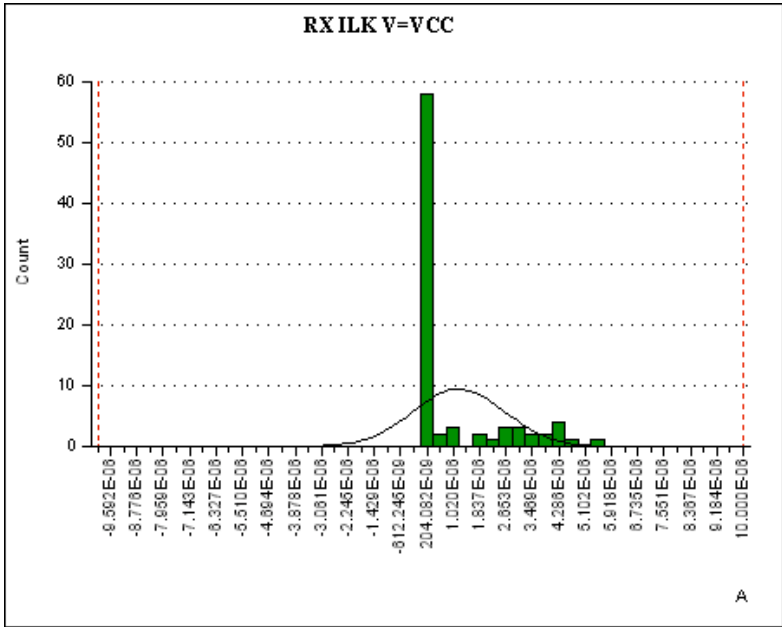
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.006, Test.Name=RX ILK V=VCC



Statistics: (A)

Max	5.602E-06	25%	324.864E-09	SpecHigh	10.000E-06
Mean	1.068E-06	10%	314.182E-09	SpecLow	-10.000E-06
Min	159.670E-09	N	82	PctWithinSpec	100.00
Range	5.442E-06	Cp	2.3707	c	
StdDev	1.406E-06	Cpl	2.6240	PctDefSpec	0
W	0.6263	Cpu	2.1175	NWithinSpec	82
WpValue	0.0000	Cpk	2.1175	NOutsideSpec	0
90%	3.602E-06	Skew	1.6722		
75%	1.049E-06	Kurtosis	1.4533		
Median	333.598E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

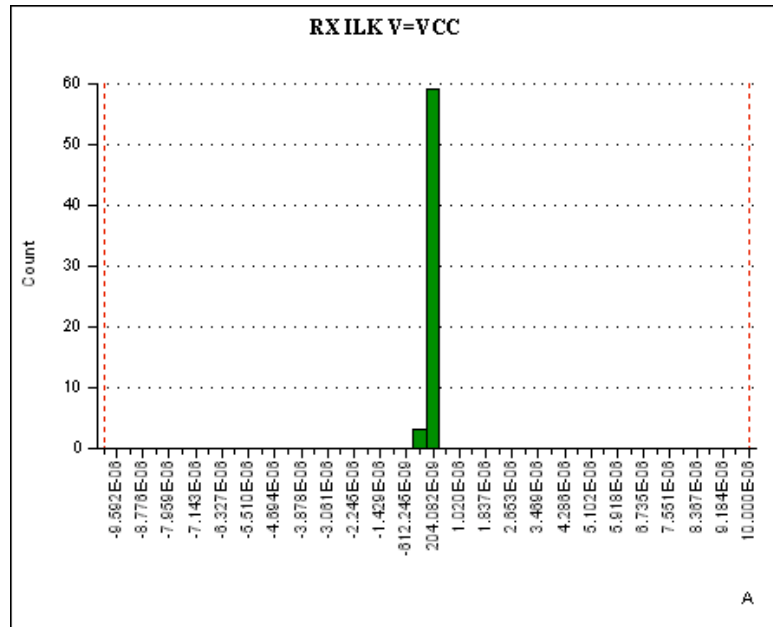
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=7.007, Test.Name=RX ILK V=VCC



Statistics: (A)

Max	169.757E-09	25%	18.253E-09	SpecHigh	10.000E-06
Mean	41.965E-09	10%	10.218E-09	SpecLow	-10.000E-06
Min	-12.233E-09	N	62	PctWithinSpec	100.00
Range	181.990E-09	Cp	>4.0000	PctDefSpec	0
StdDev	40.788E-09	Cpl	>4.0000	NWithinSpec	62
W	0.8081	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	101.384E-09	Skew	1.4841		
75%	49.733E-09	Kurtosis	1.4837		
Median	23.457E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

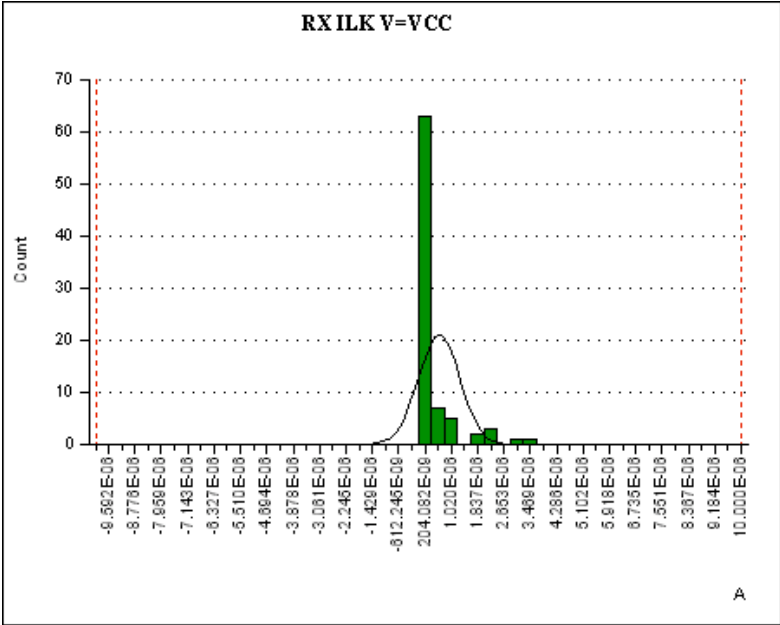
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.007, Test.Name=RX ILK V=VCC



Statistics: (A)

Max	3.325E-06	25%	283.530E-09	SpecHigh	10.000E-06
Mean	526.784E-09	10%	214.710E-09	SpecLow	-10.000E-06
Min	110.158E-09	N	82	PctWithinSpec	100.00
Range	3.215E-06	Cp	>4.0000	PctDefSpec	0
StdDev	633.412E-09	Cpl	>4.0000	NWithinSpec	82
W	0.5344	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	962.656E-09	Skew	2.9218		
75%	377.253E-09	Kurtosis	8.3449		
Median	291.782E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

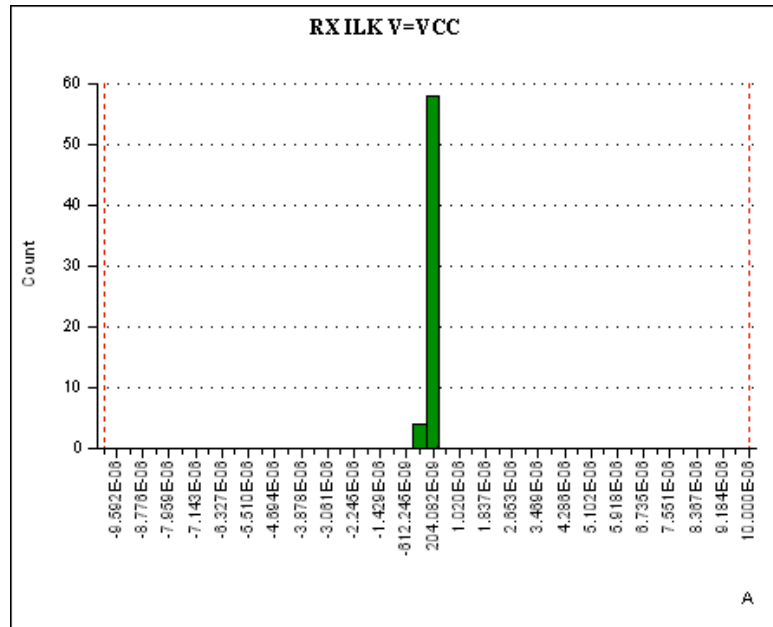
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=7.008, Test.Name=RX ILK V=VCC



Statistics: (A)

Max	190.019E-09	25%	20.240E-09	SpecHigh	10.000E-06
Mean	42.491E-09	10%	12.282E-09	SpecLow	-10.000E-06
Min	-8.180E-09	N	62	PctWithinSpec	100.00
Range	198.199E-09	Cp	>4.0000	c	
StdDev	41.614E-09	Cpl	>4.0000	PctDefSpec	0
W	0.7829	Cpu	>4.0000	NWithinSpec	62
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	97.109E-09	Skew	1.8542		
75%	55.037E-09	Kurtosis	3.4361		
Median	27.611E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

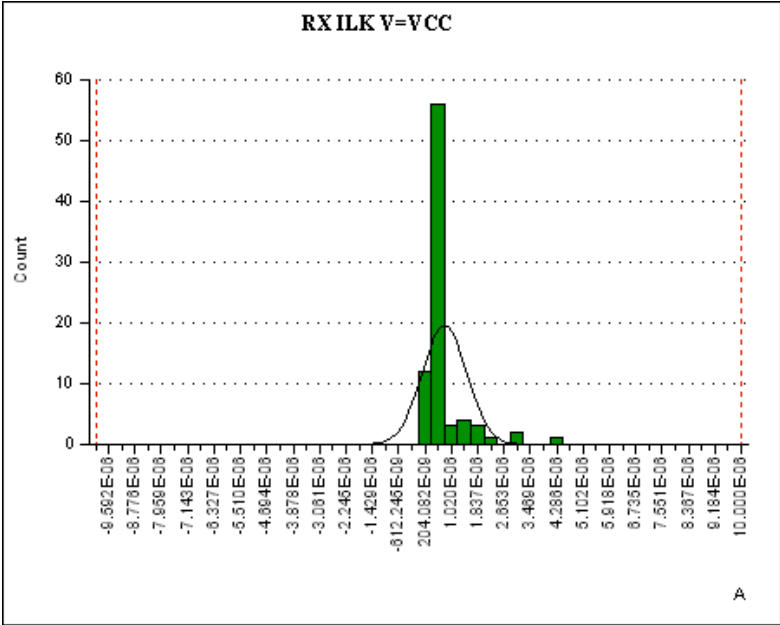
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=7.008, Test.Name=RX ILK V=VCC



Statistics: (A)

Max	4.397E-06	25%	457.789E-09	SpecHigh	10.000E-06
Mean	692.625E-09	10%	246.908E-09	SpecLow	-10.000E-06
Min	218.393E-09	N	82	PctWithinSpec	100.00
Range	4.178E-06	Cp	>4.0000	PctDefSpec	0
StdDev	676.292E-09	Cpl	>4.0000	NWithinSpec	82
W	0.5423	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	1.364E-06	Skew	3.3187		
75%	487.554E-09	Kurtosis	12.8004		
Median	472.083E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

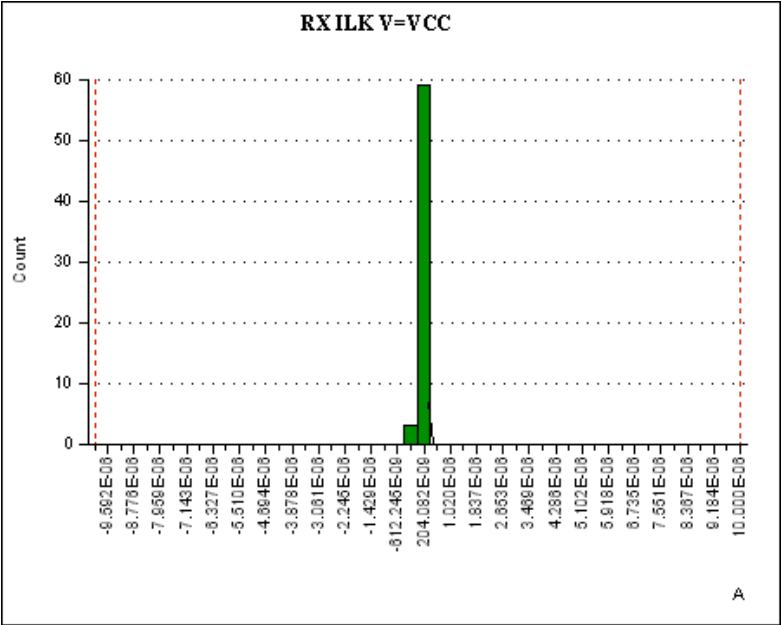
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=7.009, Test.Name=RX ILK V=VCC



Statistics: (A)

Max	241.742E-09	25%	23.999E-09	SpecHigh	10.000E-06
Mean	57.849E-09	10%	16.189E-09	SpecLow	-10.000E-06
Min	-16.213E-09	N	62	PctWithinSpec	100.00
Range	257.955E-09	Cp	>4.0000	PctDefSpec	0
StdDev	55.431E-09	Cpl	>4.0000	NWithinSpec	62
W	0.8205	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	149.172E-09	Skew	1.3599		
75%	76.112E-09	Kurtosis	1.1558		
Median	29.823E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01.AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01.AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01.AT	-	0

Data: Raw Data

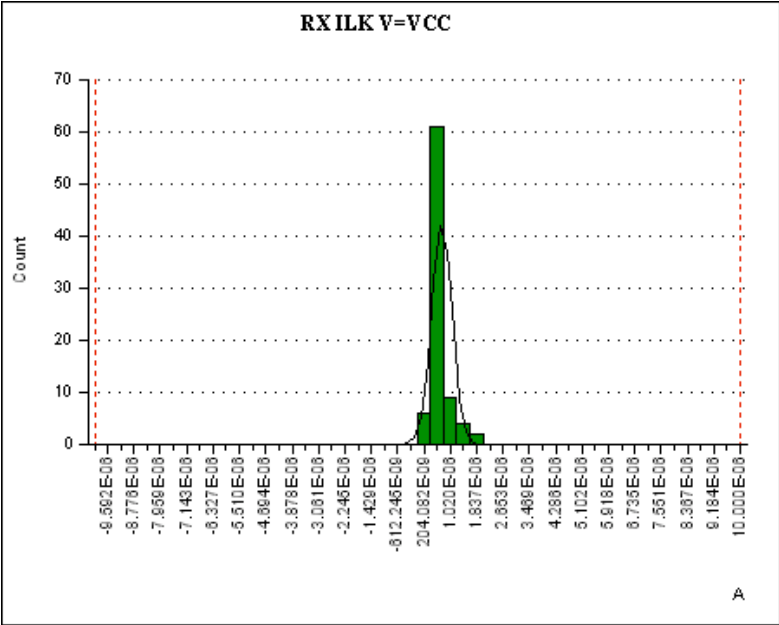
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=7.009, Test.Name=RX ILK V=VCC



Statistics: (A)

Max	1.847E-06	25%	490.721E-09	SpecHigh	10.000E-06
Mean	639.220E-09	10%	479.302E-09	SpecLow	-10.000E-06
Min	222.449E-09	N	82	PctWithinSpec	100.00
Range	1.624E-06	Cp	>4.0000	PctDefSpec	0
StdDev	315.854E-09	Cpl	>4.0000	NWithinSpec	82
W	0.6932	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	1.041E-06	Skew	2.1032		
75%	680.895E-09	Kurtosis	4.2561		
Median	503.877E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

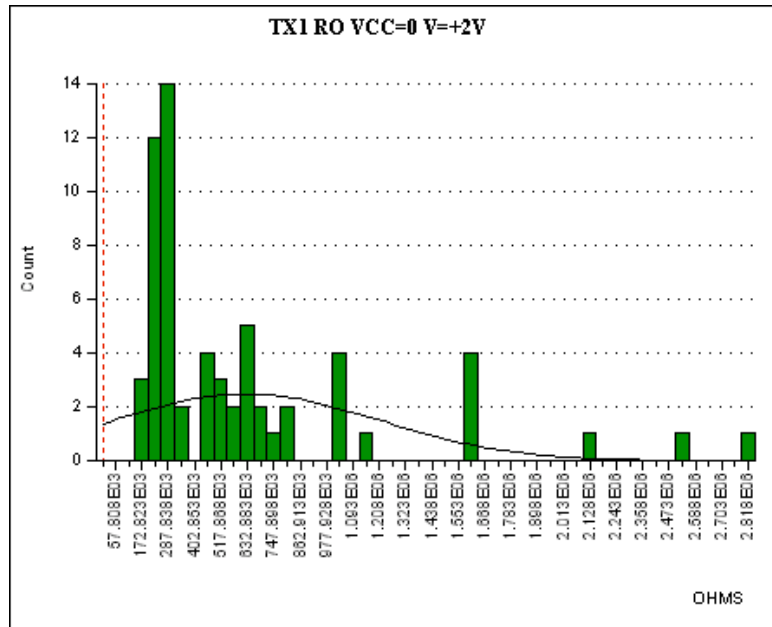
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=8.000, Test.Name=TX1 RO VCC=0 V=+2V



Statistics: (OHMS)

Max	2.818E06	25%	262.101E03	SpecHigh	N/A
Mean	624.173E03	10%	218.470E03	SpecLow	300.000
Min	173.660E03	N	62	PctWithinSpec	100.00
Range	2.645E06	Cp	N/A	PctDefSpec	0
StdDev	573.197E03	Cpl	0.3628	NWithinSpec	62
W	0.7230	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	0.3628		
90%	1.609E06	Skew	2.1326		
75%	703.513E03	Kurtosis	4.6402		
Median	403.467E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

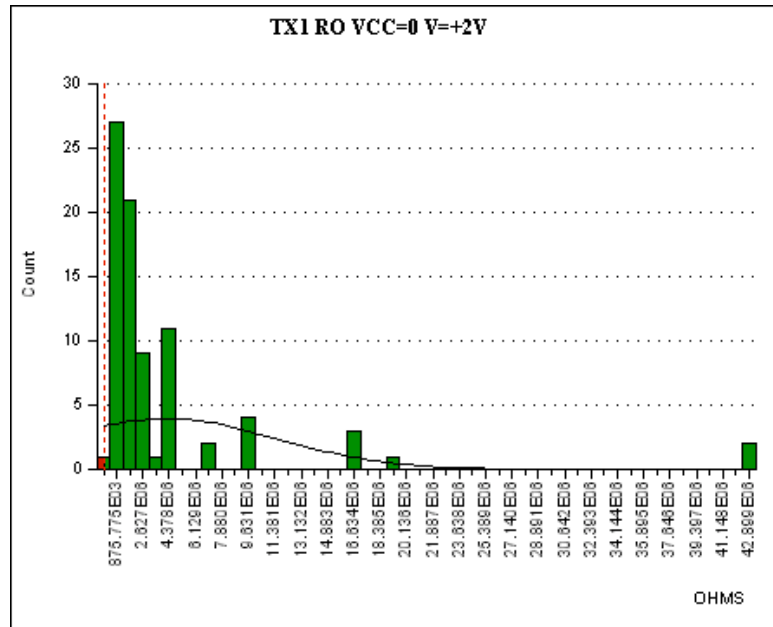
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=8.000, Test.Name=TX1 RO VCC=0 V=+2V



Statistics: (OHMS)

Max	42.899E06	25%	924.711E03	SpecHigh	N/A
Mean	4.169E06	10%	781.718E03	SpecLow	300.000
Min	277.543E03	N	82	PctWithinSpec	100.00
Range	42.621E06	Cp	N/A	c	
StdDev	7.263E06	Cpl	0.1913	PctDefSpec	0
W	0.4827	Cpu	N/A	NWithinSpec	82
WpValue	0.0000	Cpk	0.1913	NOutsideSpec	0
90%	10.044E06	Skew	4.0854		
75%	4.110E06	Kurtosis	18.8442		
Median	1.961E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

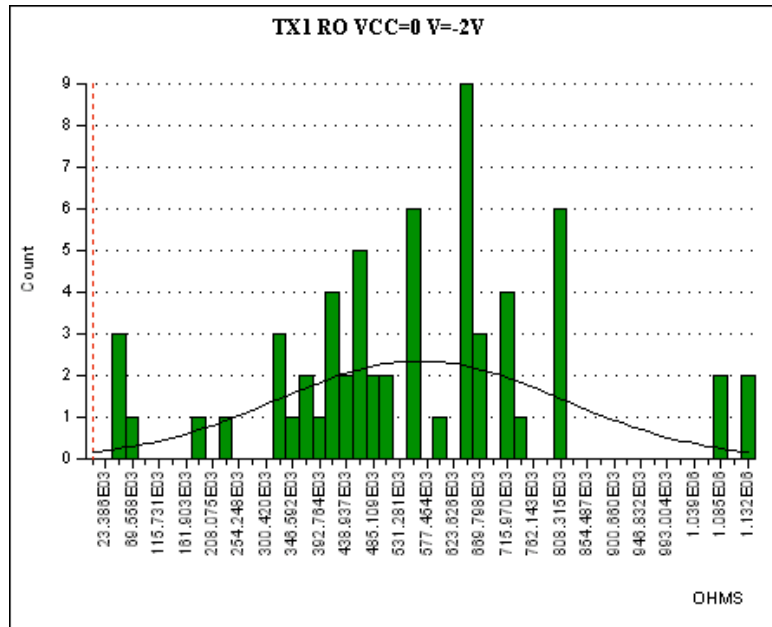
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=8.001, Test.Name=TX1 RO VCC=0 V=-2V



Statistics: (OHMS)

Max	1.132E06	25%	418.981E03	SpecHigh	N/A
Mean	560.779E03	10%	329.562E03	SpecLow	300.000
Min	40.792E03	N	62	PctWithinSpec	100.00
Range	1.091E06	Cp	N/A	PctDefSpec	0
StdDev	242.708E03	Cpl	0.7698	NWithinSpec	62
W	0.9655	Cpu	N/A	NOutsideSpec	0
WpValue	0.0785	Cpk	0.7698		
90%	815.200E03	Skew	0.1201		
75%	679.133E03	Kurtosis	0.5134		
Median	553.491E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

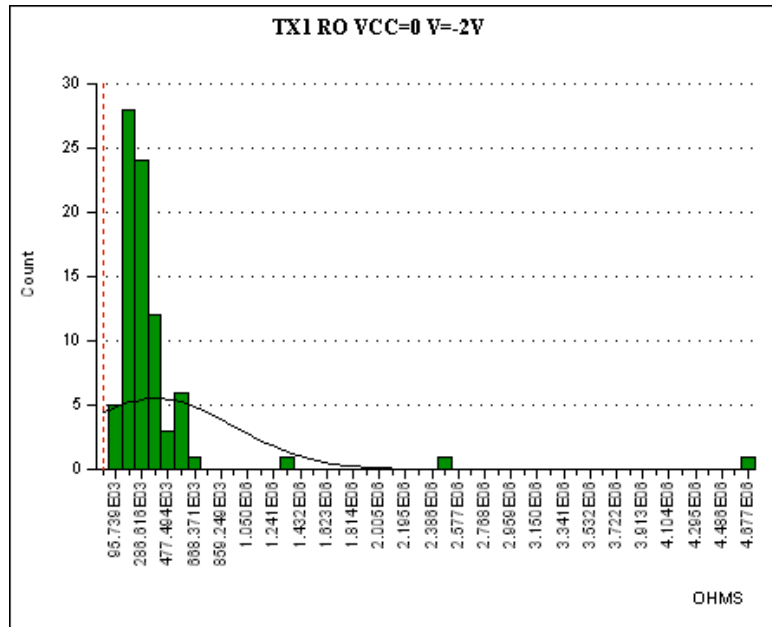
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=8.001, Test.Name=TX1 RO VCC=0 V=-2V



Statistics: (OHMS)

Max	4.677E06	25%	195.376E03	SpecHigh	N/A
Mean	380.678E03	10%	162.684E03	SpecLow	300.000
Min	126.593E03	N	82	PctWithinSpec	100.00
Range	4.550E06	Cp	N/A	PctDefSpec	0
StdDev	566.047E03	Cpl	0.2240	NWithinSpec	82
W	0.3366	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	0.2240		
90%	531.500E03	Skew	6.2675		
75%	352.874E03	Kurtosis	43.8691		
Median	256.458E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

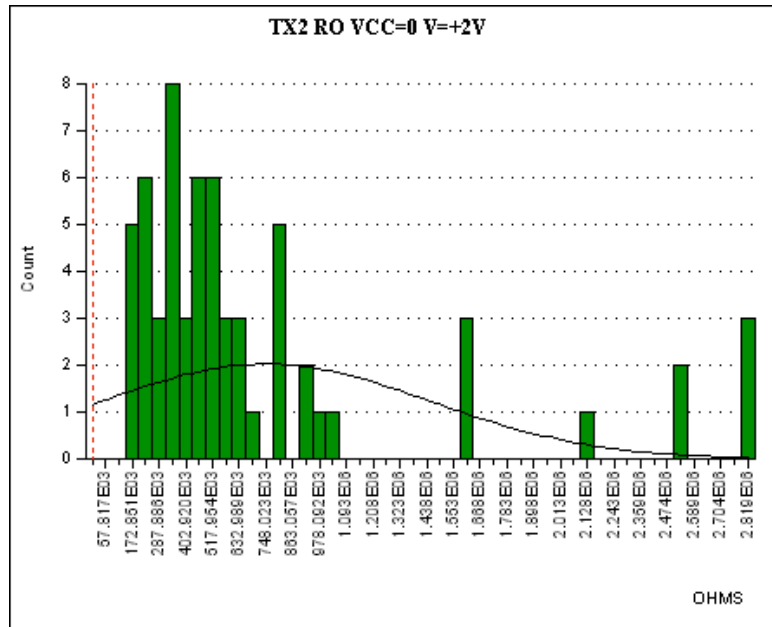
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=8.003, Test.Name=TX2 RO VCC=0 V=+2V



Statistics: (OHMS)

Max	2.819E06	25%	349.046E03	SpecHigh	N/A
Mean	739.112E03	10%	213.147E03	SpecLow	300.000
Min	163.899E03	N	62	PctWithinSpec	100.00
Range	2.655E06	Cp	N/A	PctDefSpec	0
StdDev	702.059E03	Cpl	0.3508	NWithinSpec	62
W	0.7010	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	0.3508		
90%	1.609E06	Skew	1.9946		
75%	787.967E03	Kurtosis	3.1131		
Median	489.183E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

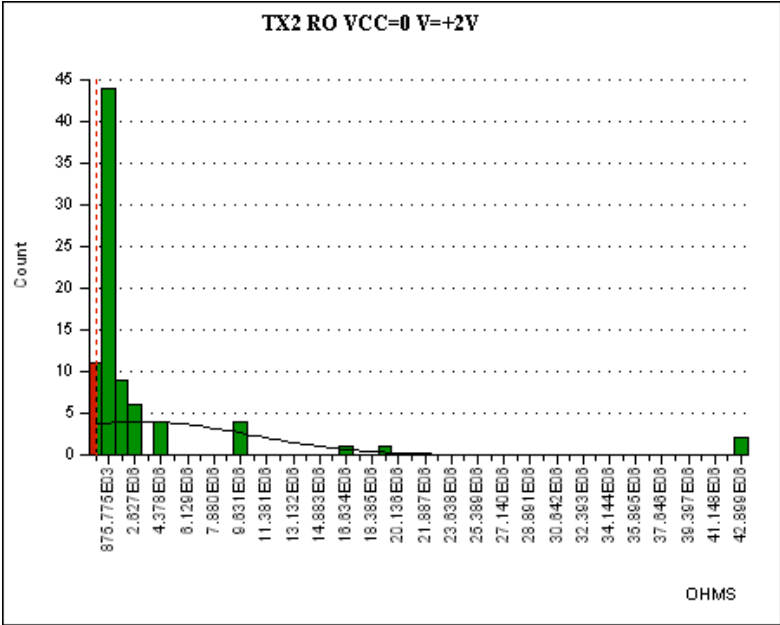
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=8.003, Test.Name=TX2 RO VCC=0 V=+2V



Statistics: (OHMS)

Max	42.899E06	25%	563.563E03	SpecHigh	N/A
Mean	3.016E06	10%	394.268E03	SpecLow	300.000
Min	106.903E03	N	82	PctWithinSpec	100.00
Range	42.792E06	Cp	N/A	PctDefSpec	0
StdDev	7.136E06	Cpl	0.1409	NWithinSpec	82
W	0.3790	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	0.1409		
90%	4.677E06	Skew	4.6456		
75%	1.961E06	Kurtosis	23.2406		
Median	858.443E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

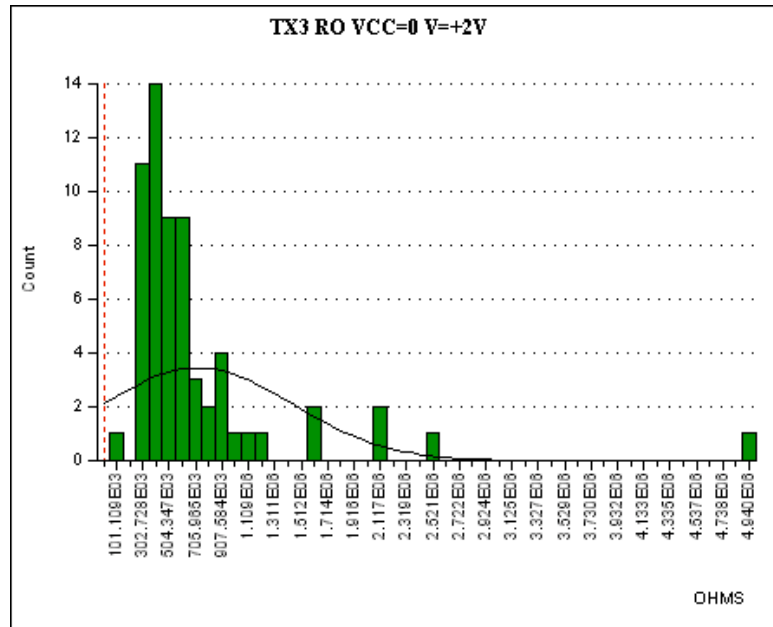
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=8.004, Test.Name=TX3 RO VCC=0 V=+2V



Statistics: (OHMS)

Max	4.940E06	25%	358.584E03	SpecHigh	N/A
Mean	714.833E03	10%	331.414E03	SpecLow	300.000
Min	116.541E03	N	62	PctWithinSpec	100.00
Range	4.823E06	Cp	N/A	PctDefSpec	0
StdDev	722.454E03	Cpl	0.3297	NWithinSpec	62
W	0.5671	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	0.3297		
90%	1.232E06	Skew	3.9235		
75%	703.513E03	Kurtosis	19.4208		
Median	475.677E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

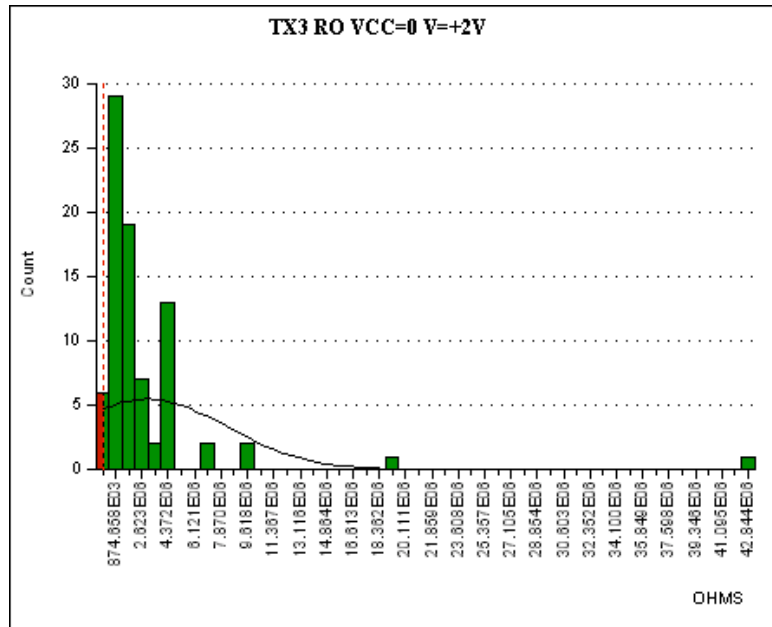
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=8.004, Test.Name=TX3 RO VCC=0 V=+2V



Statistics: (OHMS)

Max	42.844E06	25%	781.755E03	SpecHigh	N/A
Mean	2.924E06	10%	540.343E03	SpecLow	300.000
Min	269.010E03	N	82	PctWithinSpec	100.00
Range	42.575E06	Cp	N/A	PctDefSpec	0
StdDev	5.220E06	Cpl	0.1867	NWithinSpec	82
W	0.4059	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	0.1867		
90%	4.677E06	Skew	6.0719		
75%	3.554E06	Kurtosis	43.6609		
Median	1.686E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

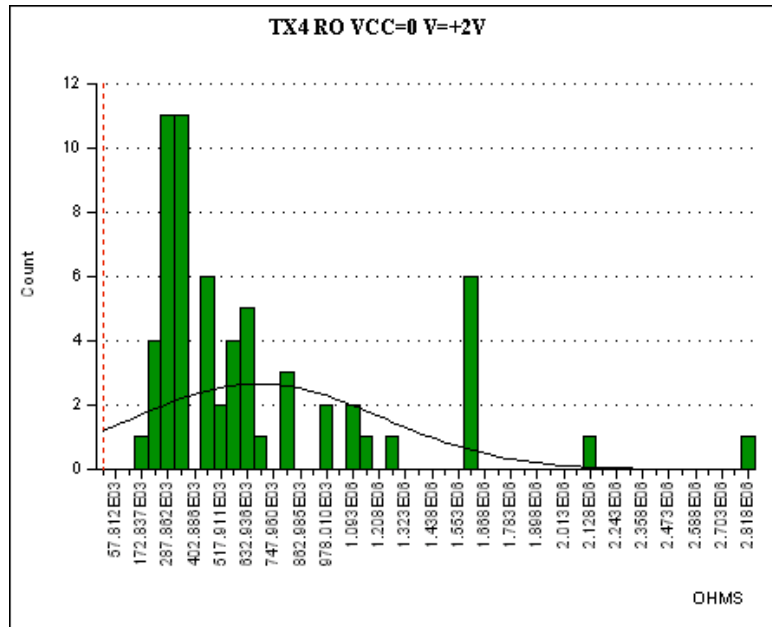
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=8.007, Test.Name=TX4 RO VCC=0 V=+2V



Statistics: (OHMS)

Max	2.818E06	25%	311.733E03	SpecHigh	N/A
Mean	672.758E03	10%	270.195E03	SpecLow	300.000
Min	153.365E03	N	62	PctWithinSpec	100.00
Range	2.665E06	Cp	N/A	PctDefSpec	0
StdDev	531.717E03	Cpl	0.4216	NWithinSpec	62
W	0.7672	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	0.4216		
90%	1.609E06	Skew	1.9027		
75%	787.967E03	Kurtosis	3.8968		
Median	466.600E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01.AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01.AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01.AT	-	0

Data: Raw Data

Stat limits applied

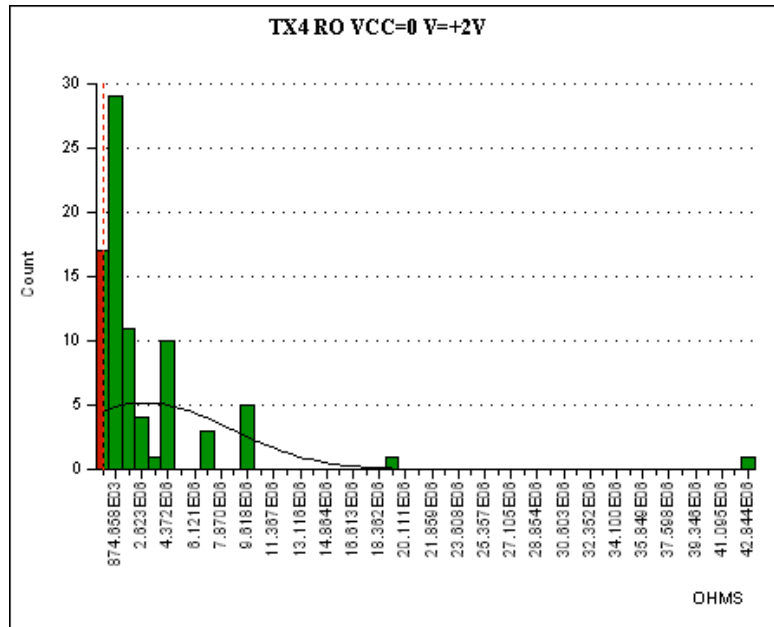
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=8.007, Test.Name=TX4 RO VCC=0 V=+2V



Statistics: (OHMS)

Max	42.844E06	25%	489.918E03	SpecHigh	N/A
Mean	2.888E06	10%	306.729E03	SpecLow	300.000
Min	147.847E03	N	82	PctWithinSpec	100.00
Range	42.696E06	Cp	N/A	PctDefSpec	0
StdDev	5.507E06	Cpl	0.1748	NWithinSpec	82
W	0.4649	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	0.1748		
90%	7.266E06	Skew	5.2600		
75%	3.553E06	Kurtosis	34.9140		
Median	1.026E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

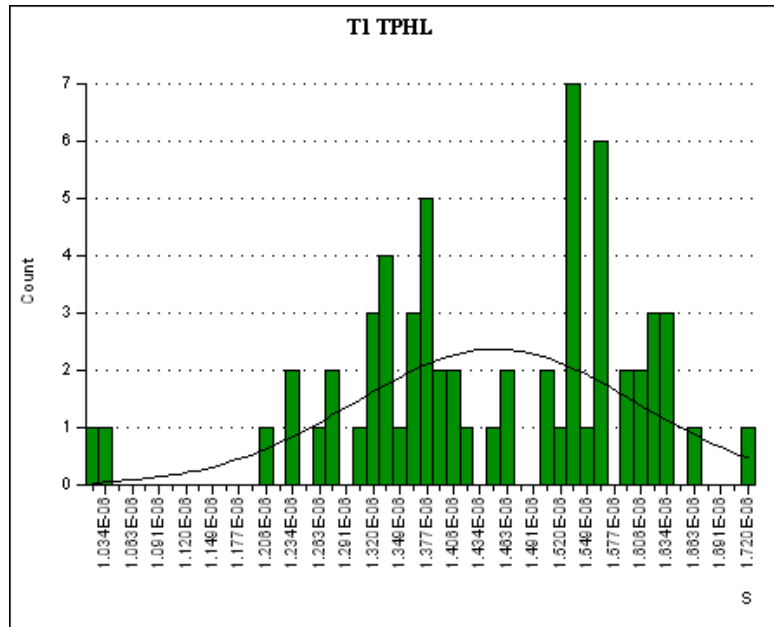
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=9.000, Test.Name=T1 TPHL



Statistics: (S)

Max	1.720E-06	25%	1.340E-06	SpecHigh	N/A
Mean	1.446E-06	10%	1.280E-06	SpecLow	N/A
Min	1.020E-06	N	62	PctWithinSpec	N/A
Range	700.000E-09	Cp	N/A	PctDefSpec	N/A
StdDev	148.904E-09	Cpl	N/A	NWithinSpec	N/A
W	0.9511	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0150	Cpk	N/A		
90%	1.620E-06	Skew	-0.5873		
75%	1.560E-06	Kurtosis	0.2793		
Median	1.455E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

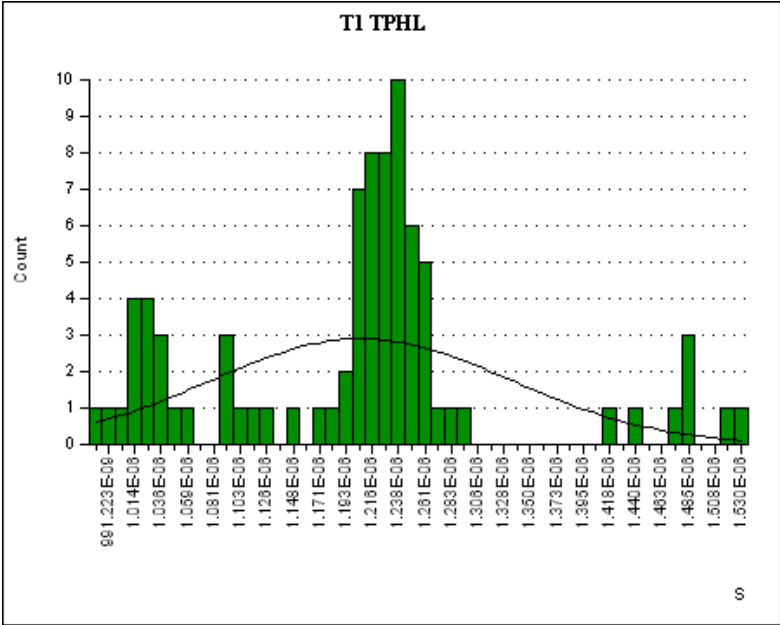
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.000, Test.Name=T1 TPHL



Statistics: (S)

Max	1.530E-06	25%	1.110E-06	SpecHigh	N/A
Mean	1.204E-06	10%	1.020E-06	SpecLow	N/A
Min	979.999E-09	N	82	PctWithinSpec	N/A
Range	550.000E-09	Cp	N/A	c	
StdDev	126.501E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8942	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	1.290E-06	Skew	0.4367		
75%	1.250E-06	Kurtosis	0.5669		
Median	1.220E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

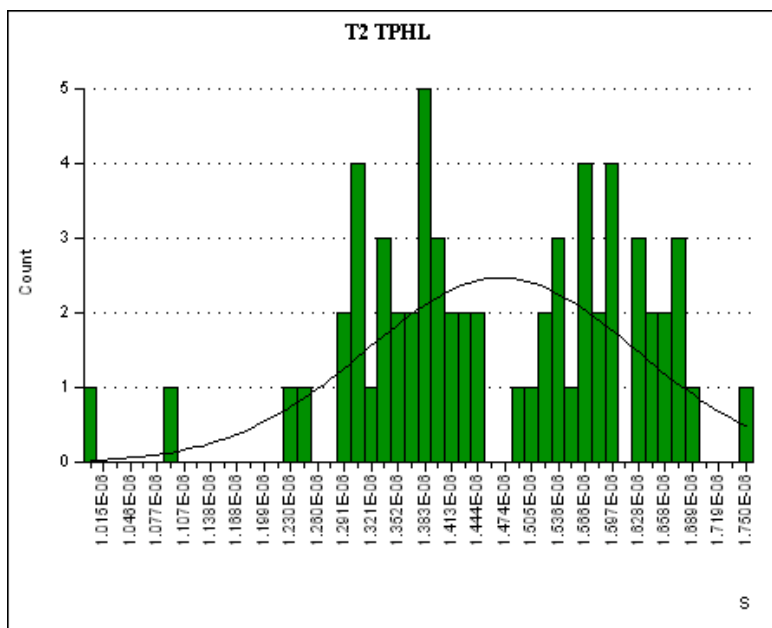
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=9.001, Test.Name=T2 TPHL



Statistics: (S)

Max	1.750E-06	25%	1.350E-06	SpecHigh	N/A
Mean	1.465E-06	10%	1.300E-06	SpecLow	N/A
Min	999.999E-09	N	62	PctWithinSpec	N/A
Range	749.999E-09	Cp	N/A	PctDefSpec	N/A
StdDev	153.545E-09	Cpl	N/A	NWithinSpec	N/A
W	0.9593	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0383	Cpk	N/A		
90%	1.660E-06	Skew	-0.4689		
75%	1.590E-06	Kurtosis	0.1704		
Median	1.440E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

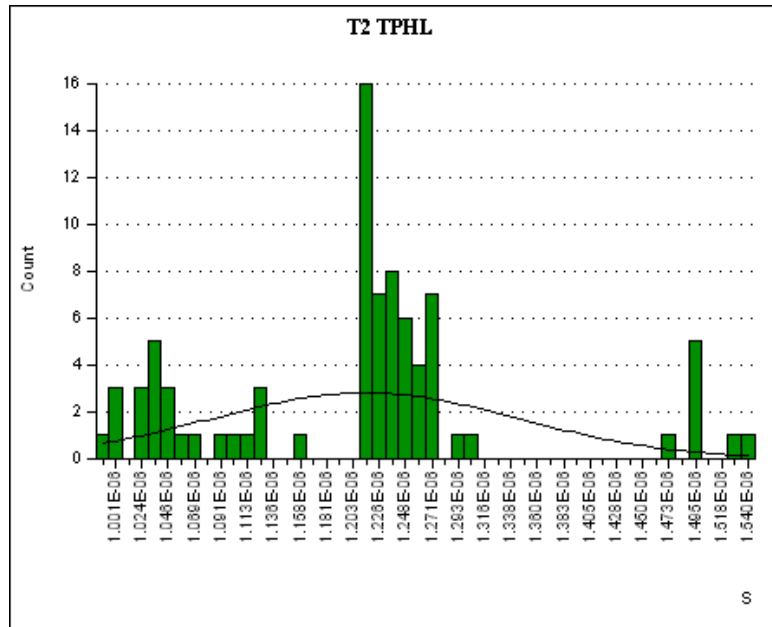
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.001, Test.Name=T2 TPHL



Statistics: (S)

Max	1.540E-06	25%	1.120E-06	SpecHigh	N/A
Mean	1.212E-06	10%	1.030E-06	SpecLow	N/A
Min	989.999E-09	N	82	PctWithinSpec	N/A
Range	550.000E-09	Cp	N/A	PctDefSpec	N/A
StdDev	130.379E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8850	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.300E-06	Skew	0.4990		
75%	1.260E-06	Kurtosis	0.5465		
Median	1.230E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

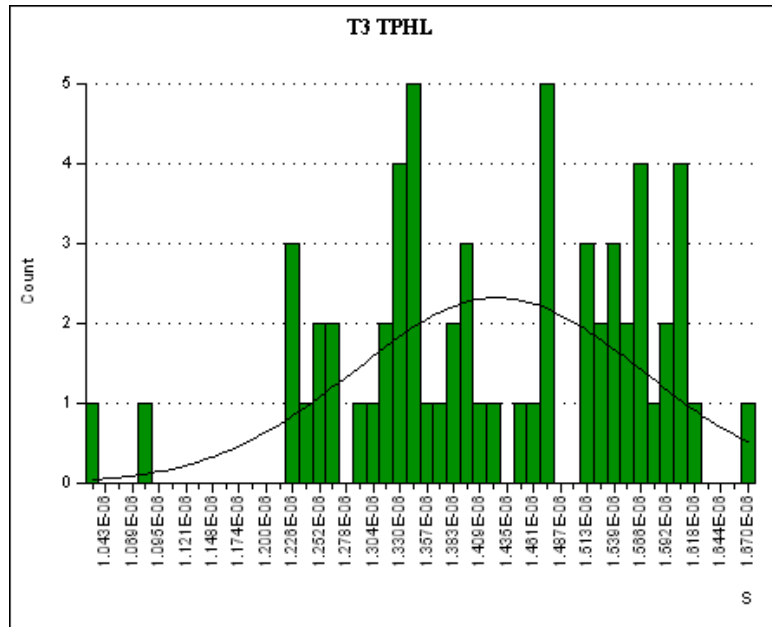
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.002, Test.Name=T3 TPHL



Statistics: (S)

Max	1.670E-06	25%	1.330E-06	SpecHigh	N/A
Mean	1.422E-06	10%	1.250E-06	SpecLow	N/A
Min	1.030E-06	N	62	PctWithinSpec	N/A
Range	639.999E-09	Cp	N/A	PctDefSpec	N/A
StdDev	139.278E-09	Cpl	N/A	NWithinSpec	N/A
W	0.9580	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0329	Cpk	N/A		
90%	1.590E-06	Skew	-0.4583		
75%	1.540E-06	Kurtosis	-0.1812		
Median	1.415E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

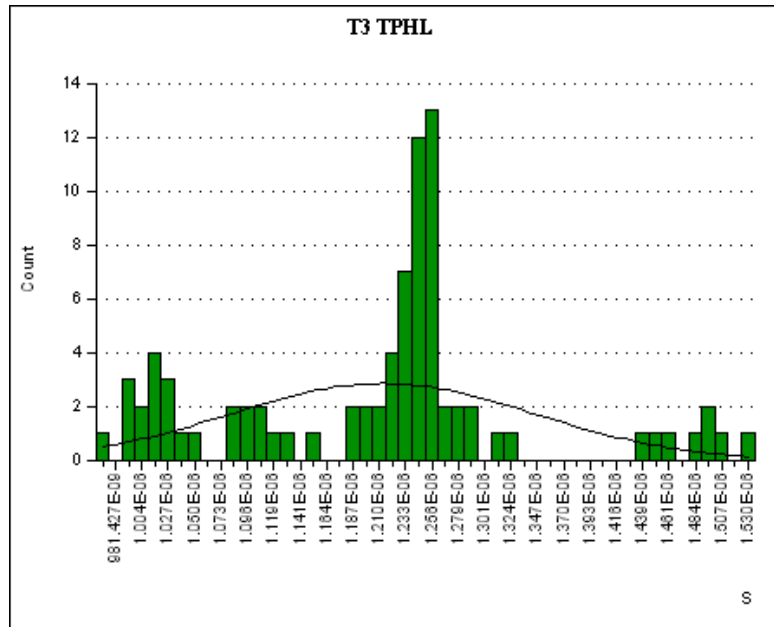
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.002, Test.Name=T3 TPHL



Statistics: (S)

Max	1.530E-06	25%	1.110E-06	SpecHigh	N/A
Mean	1.211E-06	10%	1.020E-06	SpecLow	N/A
Min	969.999E-09	N	82	PctWithinSpec	N/A
Range	560.000E-09	Cp	N/A	PctDefSpec	N/A
StdDev	130.192E-09	Cpl	N/A	NWithinSpec	N/A
W	0.9106	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.320E-06	Skew	0.2705		
75%	1.260E-06	Kurtosis	0.2591		
Median	1.235E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

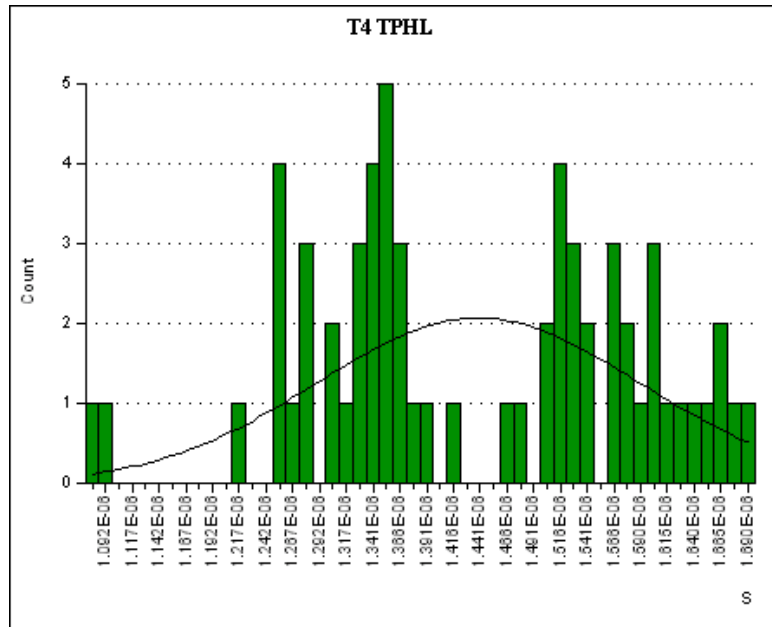
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.003, Test.Name=T4 TPHL



Statistics: (S)

Max	1.690E-06	25%	1.330E-06	SpecHigh	N/A
Mean	1.436E-06	10%	1.260E-06	SpecLow	N/A
Min	1.080E-06	N	62	PctWithinSpec	N/A
Range	610.000E-09	Cp	N/A	PctDefSpec	N/A
StdDev	148.882E-09	Cpl	N/A	NWithinSpec	N/A
W	0.9511	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0150	Cpk	N/A		
90%	1.630E-06	Skew	-0.1542		
75%	1.570E-06	Kurtosis	-0.7619		
Median	1.400E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

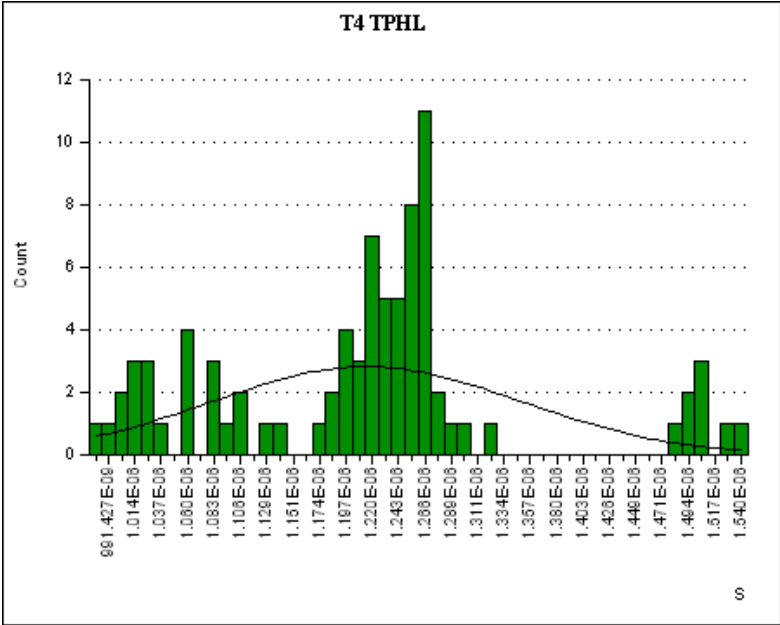
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.003, Test.Name=T4 TPHL



Statistics: (S)

Max	1.540E-06	25%	1.110E-06	SpecHigh	N/A
Mean	1.213E-06	10%	1.030E-06	SpecLow	N/A
Min	979.999E-09	N	82	PctWithinSpec	N/A
Range	560.000E-09	Cp	N/A	c	
StdDev	132.347E-09	Cpl	N/A	PctDefSpec	N/A
W	0.9035	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	1.320E-06	Skew	0.4899		
75%	1.260E-06	Kurtosis	0.5165		
Median	1.230E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

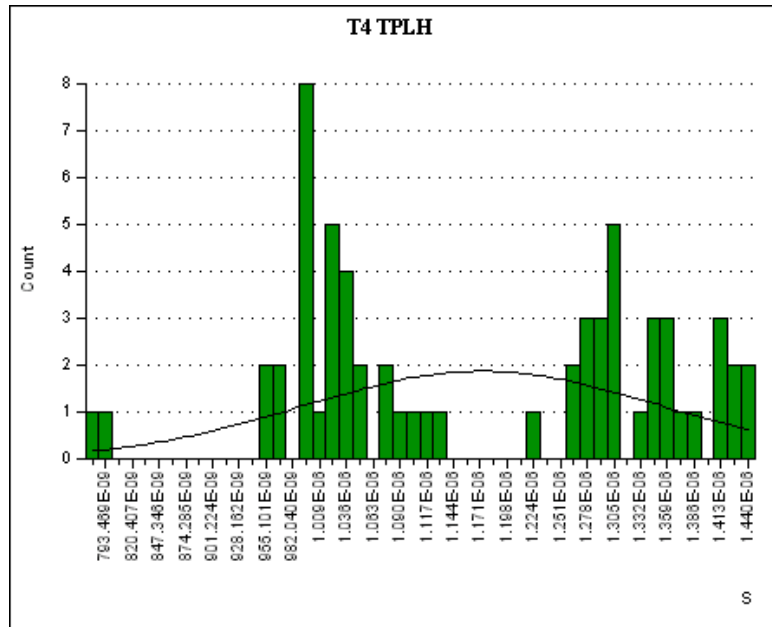
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=9.004, Test.Name=T4 TPLH



Statistics: (S)

Max	1.440E-06	25%	1.020E-06	SpecHigh	N/A
Mean	1.169E-06	10%	989.999E-09	SpecLow	N/A
Min	779.999E-09	N	62	PctWithinSpec	N/A
Range	659.999E-09	Cp	N/A	c	
StdDev	177.936E-09	Cpl	N/A	PctDefSpec	N/A
W	0.9028	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0001	Cpk	N/A	NOutsideSpec	N/A
90%	1.410E-06	Skew	-0.0893		
75%	1.330E-06	Kurtosis	-1.2410		
Median	1.125E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

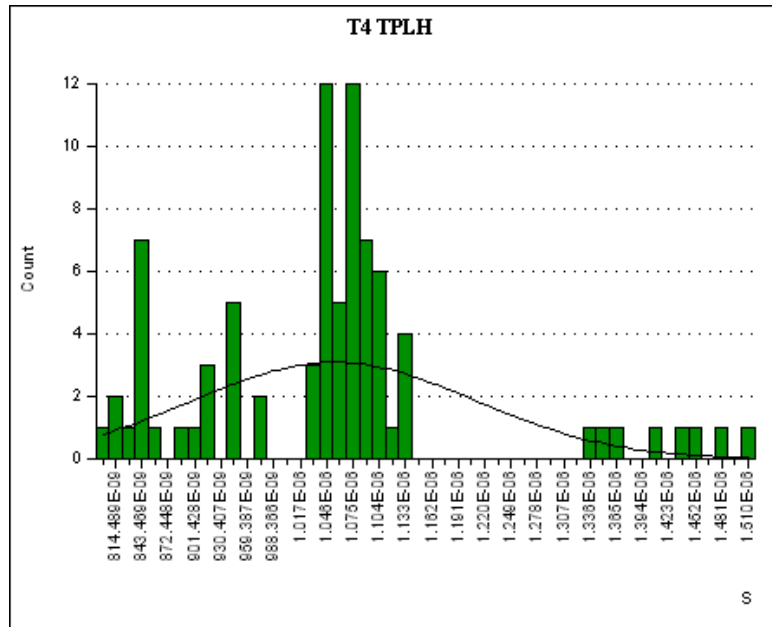
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.004, Test.Name=T4 TPLH



Statistics: (S)

Max	1.510E-06	25%	949.999E-09	SpecHigh	N/A
Mean	1.052E-06	10%	839.999E-09	SpecLow	N/A
Min	799.999E-09	N	82	PctWithinSpec	N/A
Range	709.999E-09	Cp	N/A	PctDefSpec	N/A
StdDev	153.215E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8724	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.130E-06	Skew	0.9601		
75%	1.090E-06	Kurtosis	1.5940		
Median	1.060E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

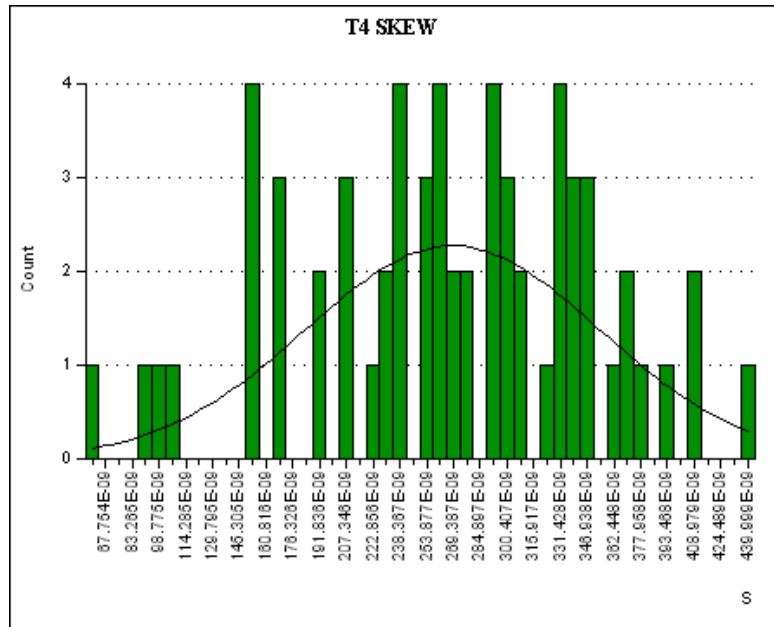
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.005, Test.Name=T4 SKEW



Statistics: (S)

Max	439.999E-09	25%	210.001E-09	SpecHigh	N/A
Mean	266.613E-09	10%	150.000E-09	SpecLow	N/A
Min	59.999E-09	N	62	PctWithinSpec	N/A
Range	380.000E-09	Cp	N/A	c	
StdDev	84.309E-09	Cpl	N/A	PctDefSpec	N/A
W	0.9847	Cpu	N/A	NWithinSpec	N/A
WpValue	0.6329	Cpk	N/A	NOutsideSpec	N/A
90%	370.000E-09	Skew	-0.3302		
75%	329.999E-09	Kurtosis	-0.2726		
Median	270.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

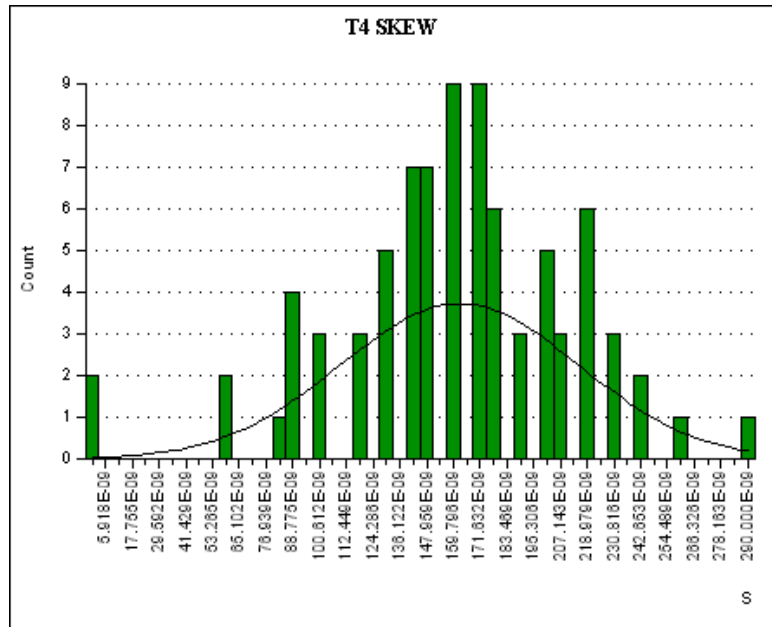
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.005, Test.Name=T4 SKEW



Statistics: (S)

Max	290.000E-09	25%	139.999E-09	SpecHigh	N/A
Mean	160.853E-09	10%	90.000E-09	SpecLow	N/A
Min	0	N	82	PctWithinSpec	N/A
Range	290.000E-09	Cp	N/A	c	
StdDev	51.907E-09	Cpl	N/A	PctDefSpec	N/A
W	0.9684	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0405	Cpk	N/A	NOutsideSpec	N/A
90%	219.999E-09	Skew	-0.5695		
75%	199.999E-09	Kurtosis	1.2305		
Median	160.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

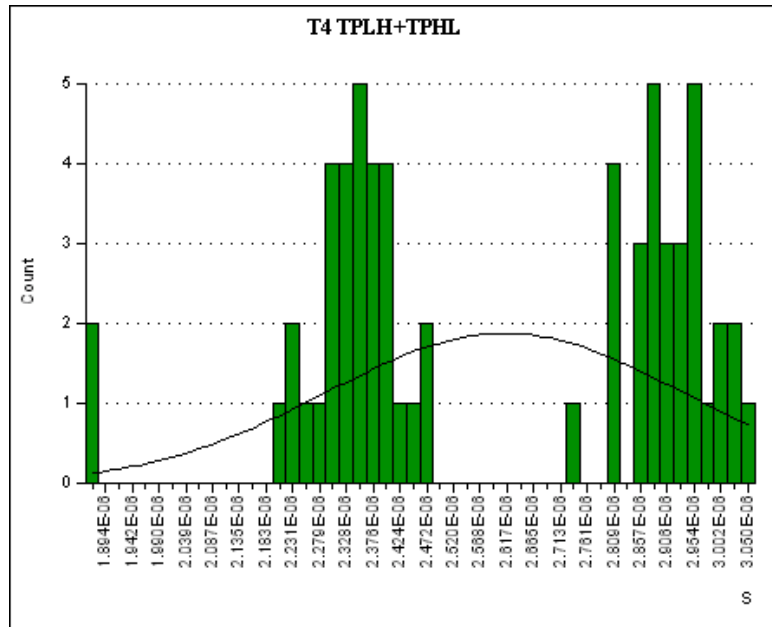
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.006, Test.Name=T4 TPLH+TPHL



Statistics: (S)

Max	3.050E-06	25%	2.340E-06	SpecHigh	N/A
Mean	2.605E-06	10%	2.280E-06	SpecLow	N/A
Min	1.870E-06	N	62	PctWithinSpec	N/A
Range	1.180E-06	Cp	N/A	PctDefSpec	N/A
StdDev	317.091E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8731	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	2.960E-06	Skew	-0.2125		
75%	2.910E-06	Kurtosis	-1.1550		
Median	2.475E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

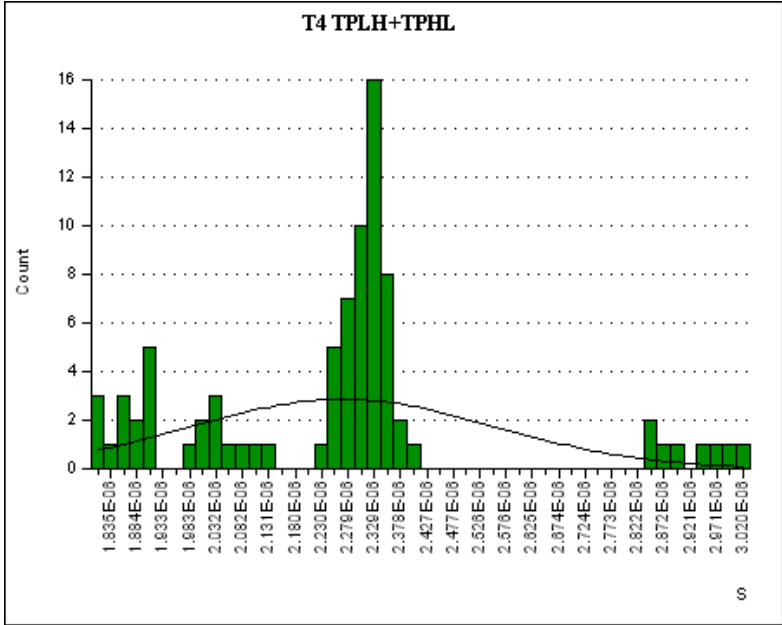
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.006, Test.Name=T4 TPLH+TPHL



Statistics: (S)

Max	3.020E-06	25%	2.050E-06	SpecHigh	N/A
Mean	2.265E-06	10%	1.890E-06	SpecLow	N/A
Min	1.810E-06	N	82	PctWithinSpec	N/A
Range	1.210E-06	Cp	N/A	c	
StdDev	281.579E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8582	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	2.400E-06	Skew	0.7499		
75%	2.340E-06	Kurtosis	1.0464		
Median	2.300E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

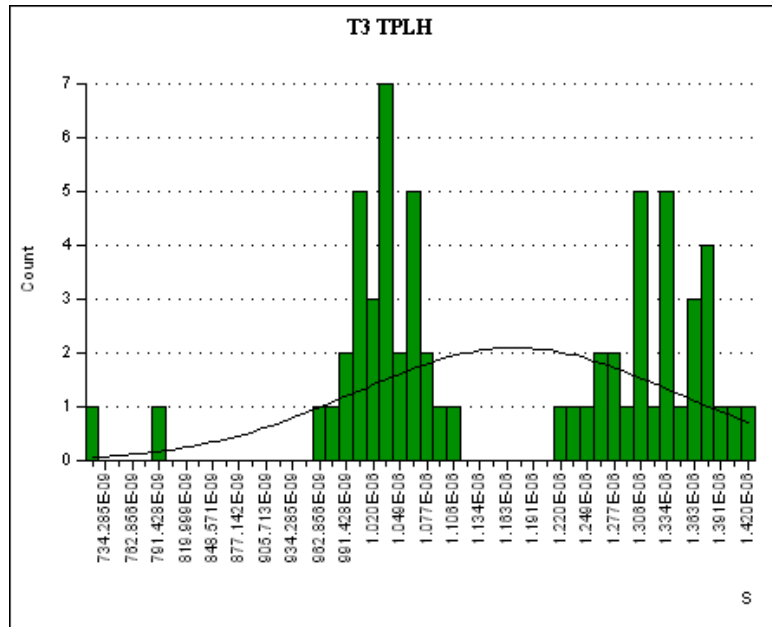
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=9.007, Test.Name=T3 TPLH



Statistics: (S)

Max	1.420E-06	25%	1.030E-06	SpecHigh	N/A
Mean	1.167E-06	10%	999.999E-09	SpecLow	N/A
Min	719.999E-09	N	62	PctWithinSpec	N/A
Range	699.999E-09	Cp	N/A	PctDefSpec	N/A
StdDev	168.402E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8928	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0001	Cpk	N/A		
90%	1.380E-06	Skew	-0.2415		
75%	1.340E-06	Kurtosis	-0.8325		
Median	1.100E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

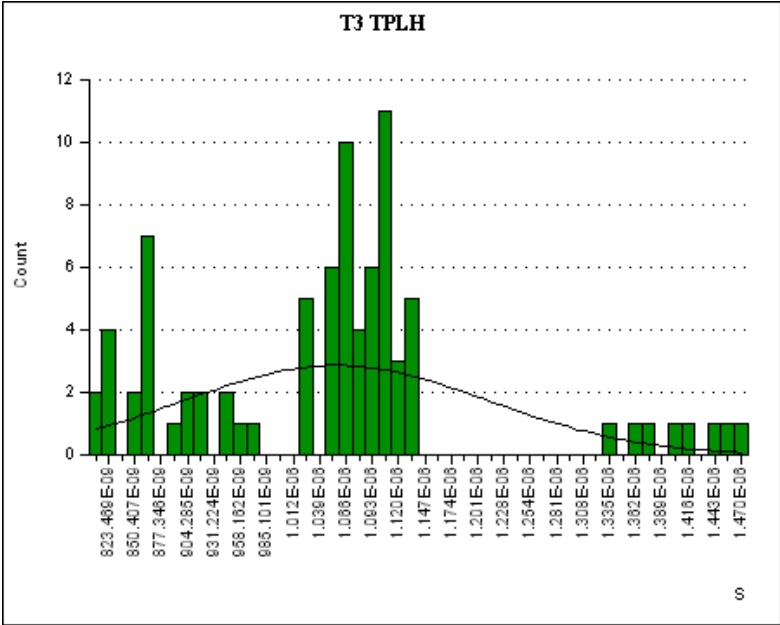
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.007, Test.Name=T3 TPLH



Statistics: (S)

Max	1.470E-06	25%	939.999E-09	SpecHigh	N/A
Mean	1.053E-06	10%	859.999E-09	SpecLow	N/A
Min	809.999E-09	N	82	PctWithinSpec	N/A
Range	659.999E-09	Cp	N/A	c	
StdDev	153.761E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8885	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	1.130E-06	Skew	0.7404		
75%	1.110E-06	Kurtosis	0.9303		
Median	1.065E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

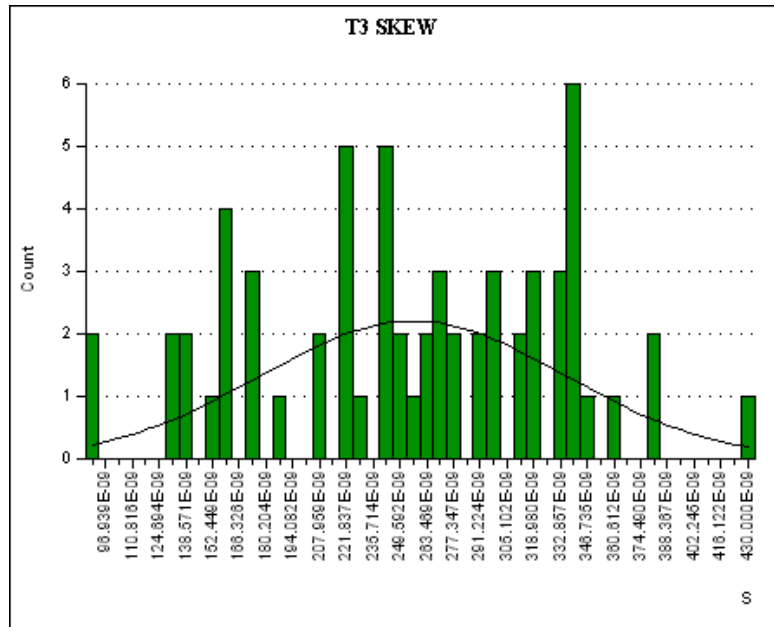
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=9.008, Test.Name=T3 SKEW



Statistics: (S)

Max	430.000E-09	25%	210.000E-09	SpecHigh	N/A
Mean	254.838E-09	10%	150.000E-09	SpecLow	N/A
Min	90.000E-09	N	62	PctWithinSpec	N/A
Range	340.000E-09	Cp	N/A	c	
StdDev	77.729E-09	Cpl	N/A	PctDefSpec	N/A
W	0.9766	Cpu	N/A	NWithinSpec	N/A
WpValue	0.2833	Cpk	N/A	NOutsideSpec	N/A
90%	340.000E-09	Skew	-0.1839		
75%	319.999E-09	Kurtosis	-0.6358		
Median	260.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

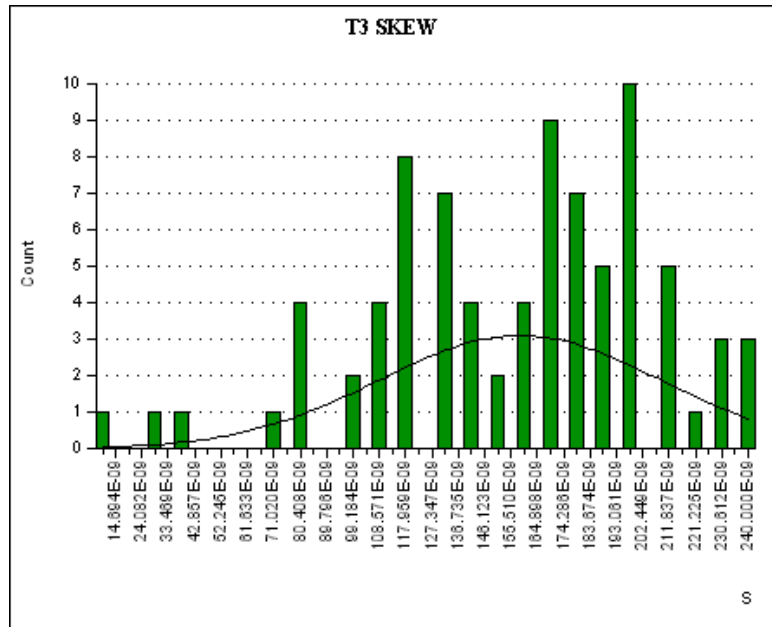
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.008, Test.Name=T3 SKEW



Statistics: (S)

Max	240.000E-09	25%	120.001E-09	SpecHigh	N/A
Mean	157.317E-09	10%	100.000E-09	SpecLow	N/A
Min	10.000E-09	N	82	PctWithinSpec	N/A
Range	230.000E-09	Cp	N/A	PctDefSpec	N/A
StdDev	49.592E-09	Cpl	N/A	NWithinSpec	N/A
W	0.9612	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0140	Cpk	N/A		
90%	210.000E-09	Skew	-0.6114		
75%	199.999E-09	Kurtosis	0.1927		
Median	170.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

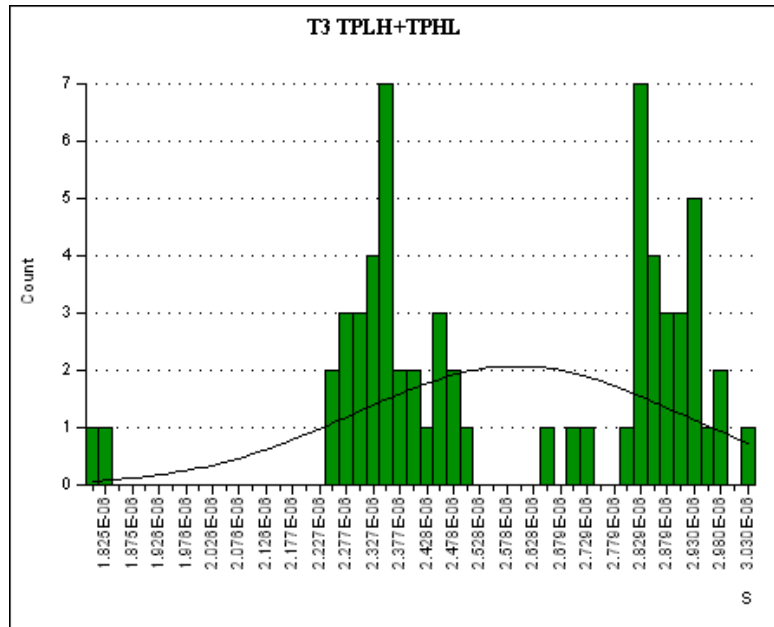
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.009, Test.Name=T3 TPLH+TPHL



Statistics: (S)

Max	3.030E-06	25%	2.340E-06	SpecHigh	N/A
Mean	2.589E-06	10%	2.280E-06	SpecLow	N/A
Min	1.800E-06	N	62	PctWithinSpec	N/A
Range	1.230E-06	Cp	N/A	PctDefSpec	N/A
StdDev	299.122E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8858	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	2.930E-06	Skew	-0.3769		
75%	2.860E-06	Kurtosis	-0.6037		
Median	2.495E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

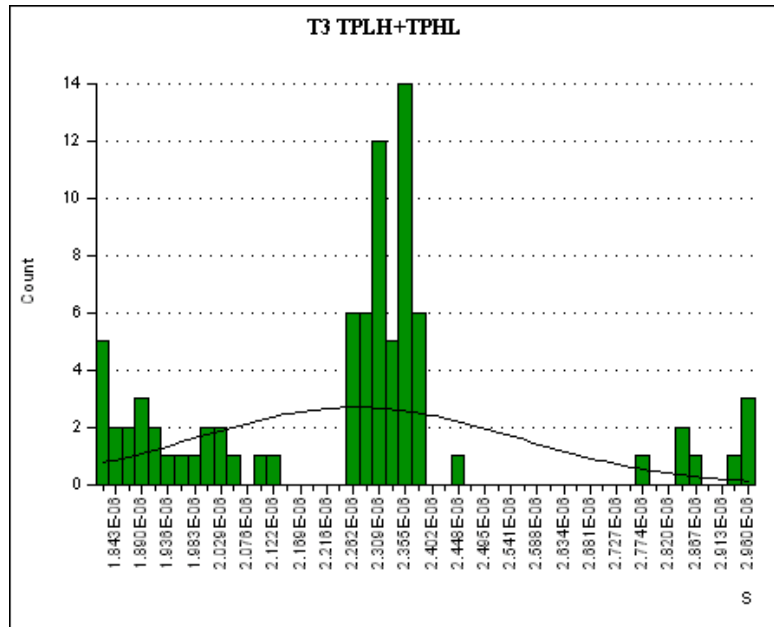
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.009, Test.Name=T3 TPLH+TPHL



Statistics: (S)

Max	2.960E-06	25%	2.040E-06	SpecHigh	N/A
Mean	2.264E-06	10%	1.860E-06	SpecLow	N/A
Min	1.820E-06	N	82	PctWithinSpec	N/A
Range	1.140E-06	Cp	N/A	c	
StdDev	280.581E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8679	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	2.440E-06	Skew	0.5298		
75%	2.350E-06	Kurtosis	0.6207		
Median	2.300E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

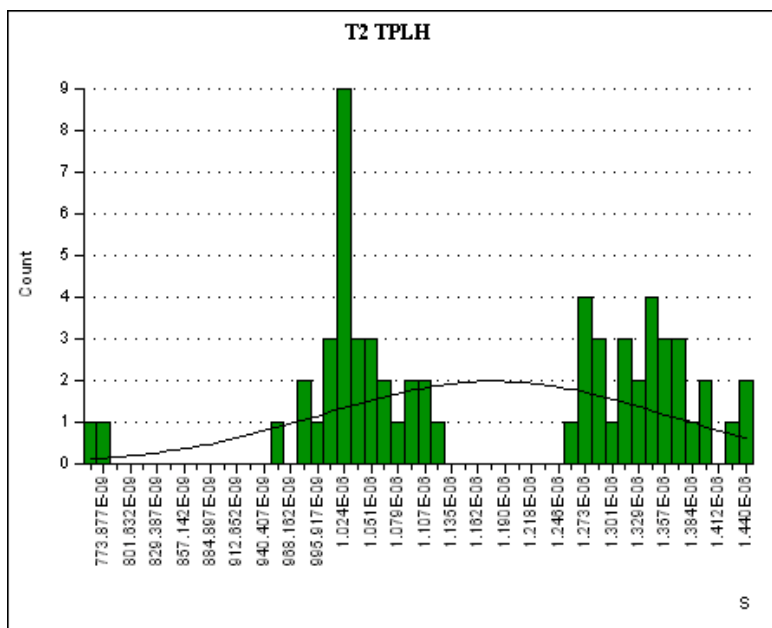
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.010, Test.Name=T2 TPLH



Statistics: (S)

Max	1.440E-06	25%	1.020E-06	SpecHigh	N/A
Mean	1.174E-06	10%	1.010E-06	SpecLow	N/A
Min	759.999E-09	N	62	PctWithinSpec	N/A
Range	679.999E-09	Cp	N/A	c	
StdDev	172.916E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8982	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0001	Cpk	N/A	NOutsideSpec	N/A
90%	1.370E-06	Skew	-0.1983		
75%	1.340E-06	Kurtosis	-0.9933		
Median	1.115E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

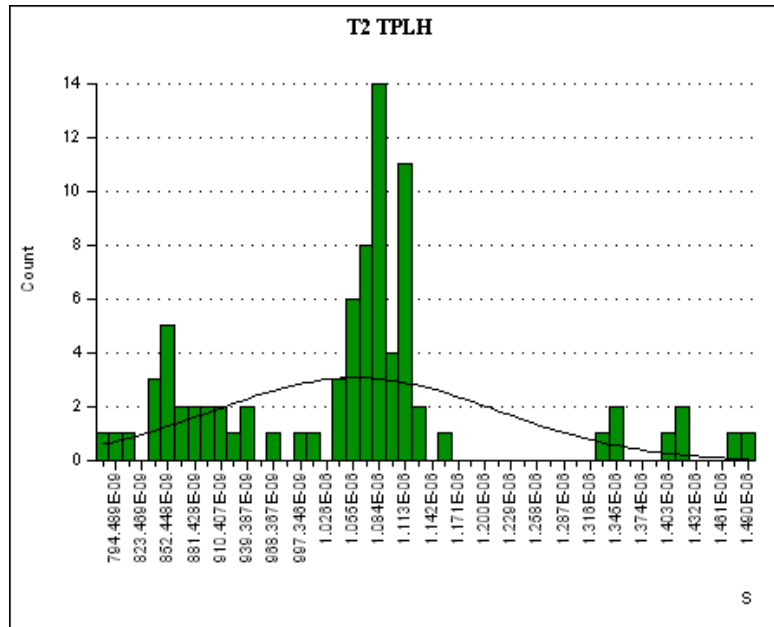
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.010, Test.Name=T2 TPLH



Statistics: (S)

Max	1.490E-06	25%	939.999E-09	SpecHigh	N/A
Mean	1.055E-06	10%	849.999E-09	SpecLow	N/A
Min	779.999E-09	N	82	PctWithinSpec	N/A
Range	709.999E-09	Cp	N/A	c	
StdDev	153.809E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8896	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	1.150E-06	Skew	0.6771		
75%	1.110E-06	Kurtosis	0.9902		
Median	1.070E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

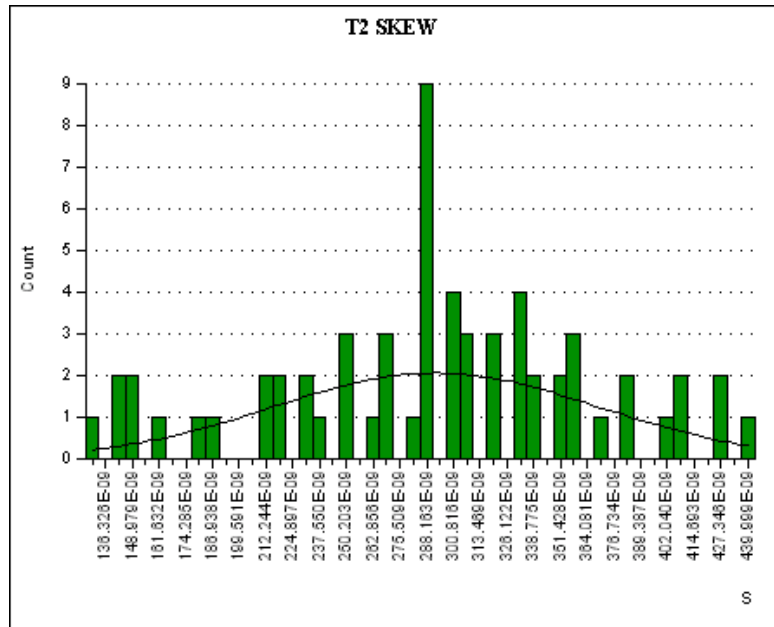
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.011, Test.Name=T2 SKEW



Statistics: (S)

Max	439.999E-09	25%	250.000E-09	SpecHigh	N/A
Mean	290.806E-09	10%	180.000E-09	SpecLow	N/A
Min	130.000E-09	N	62	PctWithinSpec	N/A
Range	309.999E-09	Cp	N/A	PctDefSpec	N/A
StdDev	75.840E-09	Cpl	N/A	NWithinSpec	N/A
W	0.9739	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.2076	Cpk	N/A		
90%	380.000E-09	Skew	-0.2534		
75%	339.999E-09	Kurtosis	-0.2608		
Median	290.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

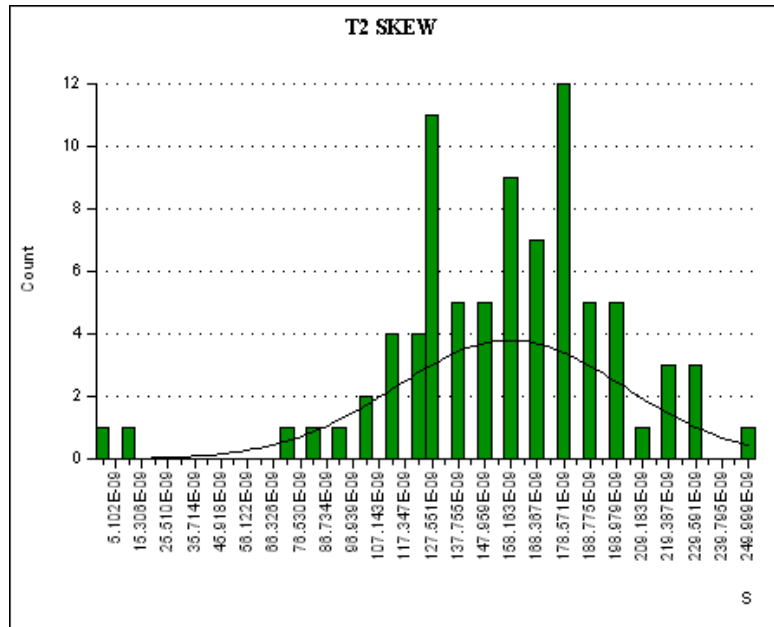
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.011, Test.Name=T2 SKEW



Statistics: (S)

Max	249.999E-09	25%	130.000E-09	SpecHigh	N/A
Mean	156.097E-09	10%	110.001E-09	SpecLow	N/A
Min	0	N	82	PctWithinSpec	N/A
Range	249.999E-09	Cp	N/A	c	
StdDev	43.935E-09	Cpl	N/A	PctDefSpec	N/A
W	0.9500	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0030	Cpk	N/A	NOutsideSpec	N/A
90%	200.000E-09	Skew	-0.8447		
75%	180.000E-09	Kurtosis	2.1026		
Median	160.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

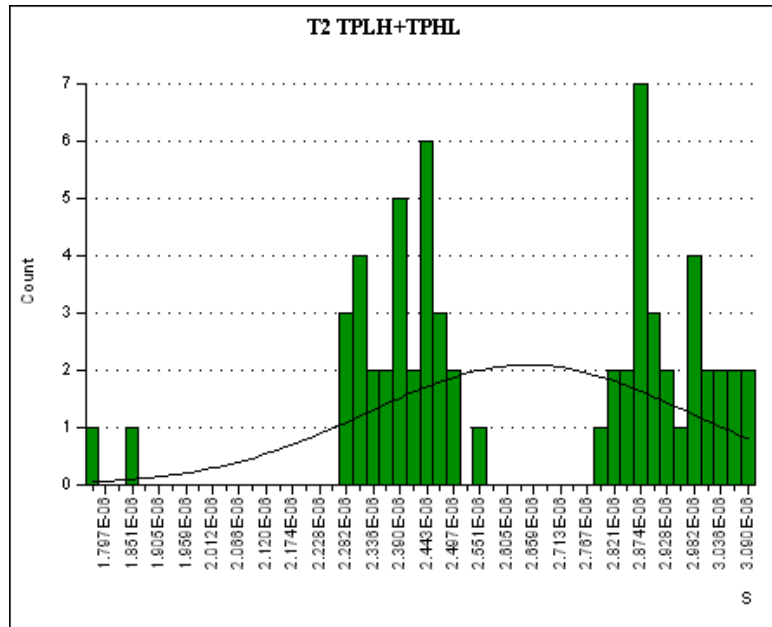
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.012, Test.Name=T2 TPLH+TPHL



Statistics: (S)

Max	3.090E-06	25%	2.390E-06	SpecHigh	N/A
Mean	2.639E-06	10%	2.310E-06	SpecLow	N/A
Min	1.770E-06	N	62	PctWithinSpec	N/A
Range	1.320E-06	Cp	N/A	PctDefSpec	N/A
StdDev	318.120E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8932	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0001	Cpk	N/A		
90%	3.010E-06	Skew	-0.3749		
75%	2.910E-06	Kurtosis	-0.5532		
Median	2.525E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

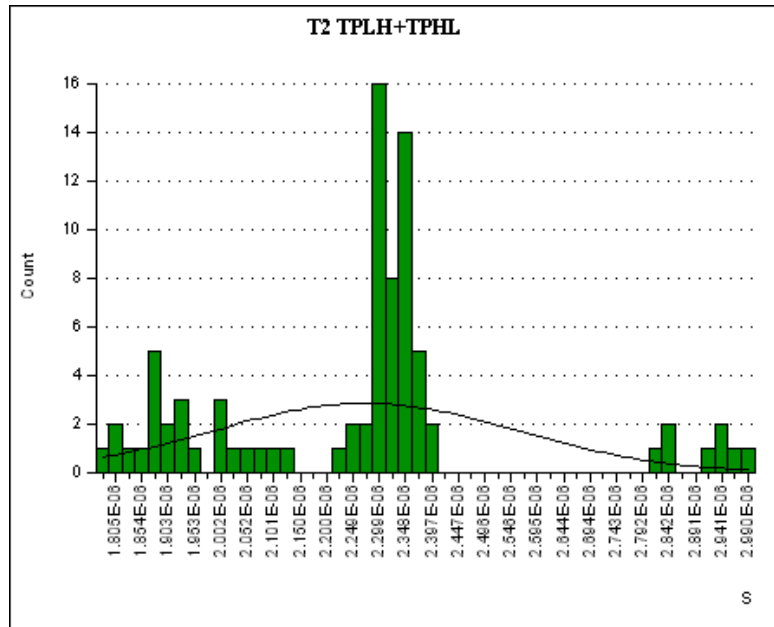
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.012, Test.Name=T2 TPLH+TPHL



Statistics: (S)

Max	2.990E-06	25%	2.060E-06	SpecHigh	N/A
Mean	2.267E-06	10%	1.870E-06	SpecLow	N/A
Min	1.780E-06	N	82	PctWithinSpec	N/A
Range	1.210E-06	Cp	N/A	c	
StdDev	281.747E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8644	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	2.400E-06	Skew	0.5859		
75%	2.350E-06	Kurtosis	0.7520		
Median	2.310E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

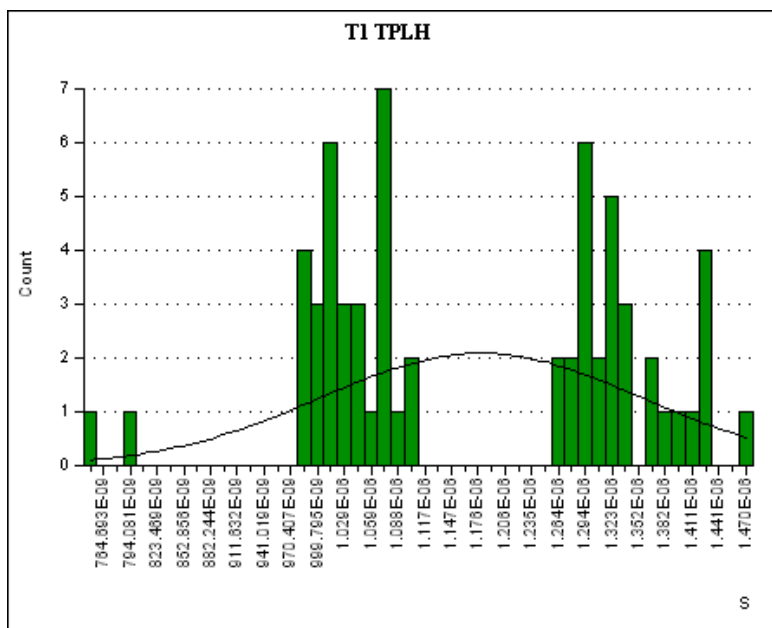
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.013, Test.Name=T1 TPLH



Statistics: (S)

Max	1.470E-06	25%	1.030E-06	SpecHigh	N/A
Mean	1.175E-06	10%	999.999E-09	SpecLow	N/A
Min	749.999E-09	N	62	PctWithinSpec	N/A
Range	719.999E-09	Cp	N/A	c	
StdDev	173.770E-09	Cpl	N/A	PctDefSpec	N/A
W	0.9043	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0001	Cpk	N/A	NOutsideSpec	N/A
90%	1.390E-06	Skew	-0.1400		
75%	1.330E-06	Kurtosis	-1.0261		
Median	1.100E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

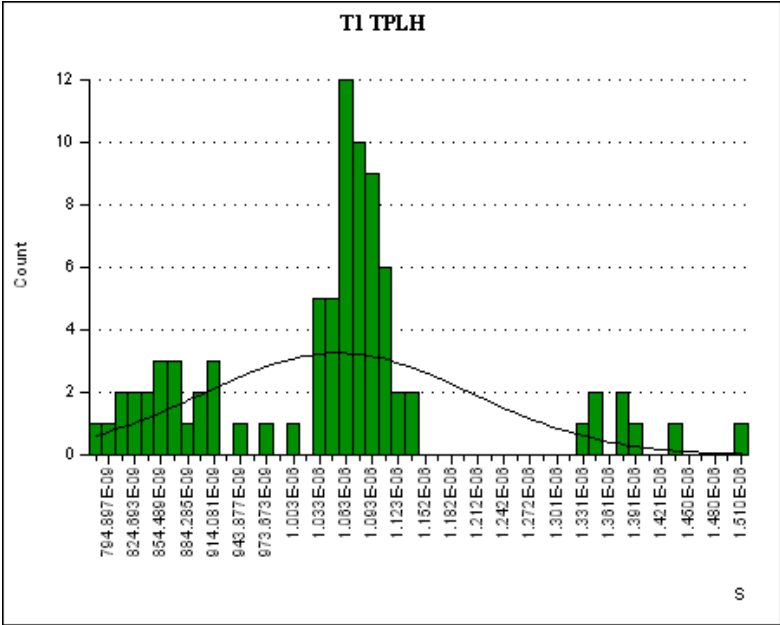
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.013, Test.Name=T1 TPLH



Statistics: (S)

Max	1.510E-06	25%	949.999E-09	SpecHigh	N/A
Mean	1.051E-06	10%	849.999E-09	SpecLow	N/A
Min	779.999E-09	N	82	PctWithinSpec	N/A
Range	729.999E-09	Cp	N/A	c	
StdDev	149.507E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8916	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	1.140E-06	Skew	0.6395		
75%	1.100E-06	Kurtosis	1.0917		
Median	1.070E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

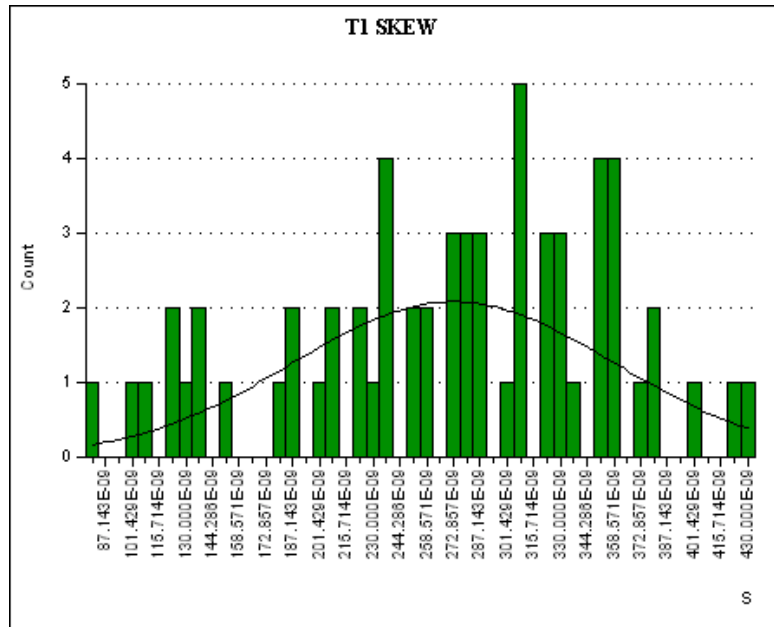
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=9.014, Test.Name=T1 SKEW



Statistics: (S)

Max	430.000E-09	25%	219.999E-09	SpecHigh	N/A
Mean	270.967E-09	10%	139.999E-09	SpecLow	N/A
Min	80.000E-09	N	62	PctWithinSpec	N/A
Range	350.000E-09	Cp	N/A	PctDefSpec	N/A
StdDev	84.770E-09	Cpl	N/A	NWithinSpec	N/A
W	0.9679	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.1039	Cpk	N/A		
90%	360.000E-09	Skew	-0.4363		
75%	330.000E-09	Kurtosis	-0.4892		
Median	280.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

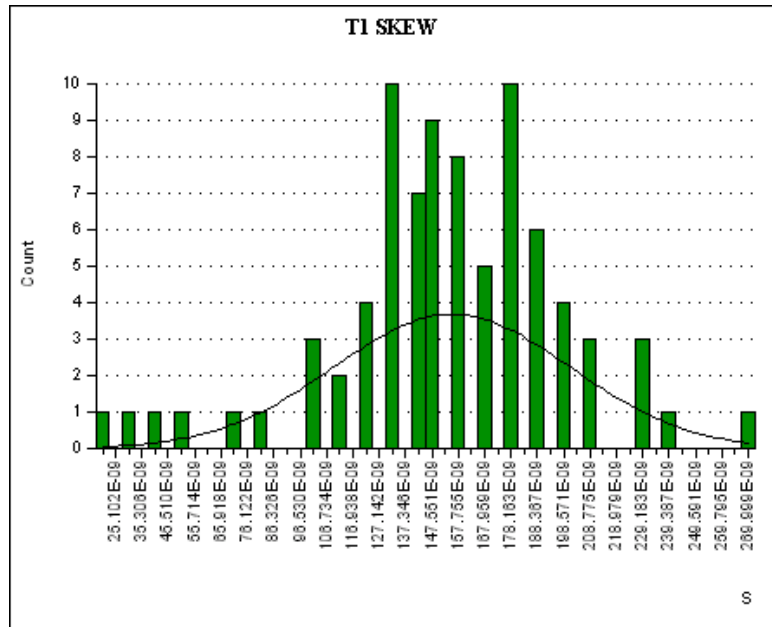
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.014, Test.Name=T1 SKEW



Statistics: (S)

Max	269.999E-09	25%	130.000E-09	SpecHigh	N/A
Mean	153.902E-09	10%	100.000E-09	SpecLow	N/A
Min	20.000E-09	N	82	PctWithinSpec	N/A
Range	249.999E-09	Cp	N/A	PctDefSpec	N/A
StdDev	45.318E-09	Cpl	N/A	NWithinSpec	N/A
W	0.9645	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0229	Cpk	N/A		
90%	200.000E-09	Skew	-0.5328		
75%	180.000E-09	Kurtosis	1.1825		
Median	155.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T		0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T		0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T		0

Data: Raw Data

Stat limits applied

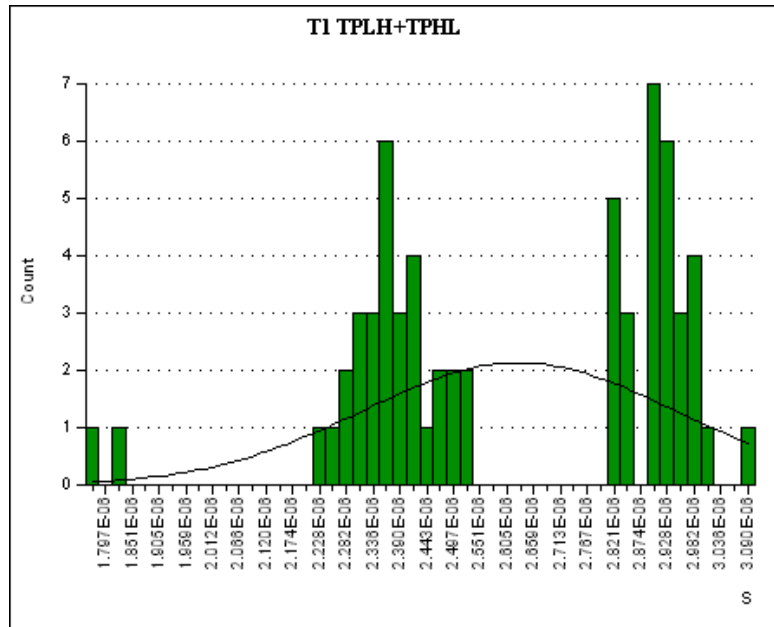
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.015, Test.Name=T1 TPLH+TPHL



Statistics: (S)

Max	3.090E-06	25%	2.360E-06	SpecHigh	N/A
Mean	2.621E-06	10%	2.310E-06	SpecLow	N/A
Min	1.770E-06	N	62	PctWithinSpec	N/A
Range	1.320E-06	Cp	N/A	PctDefSpec	N/A
StdDev	312.331E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8782	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	2.960E-06	Skew	-0.4229		
75%	2.910E-06	Kurtosis	-0.5613		
Median	2.520E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

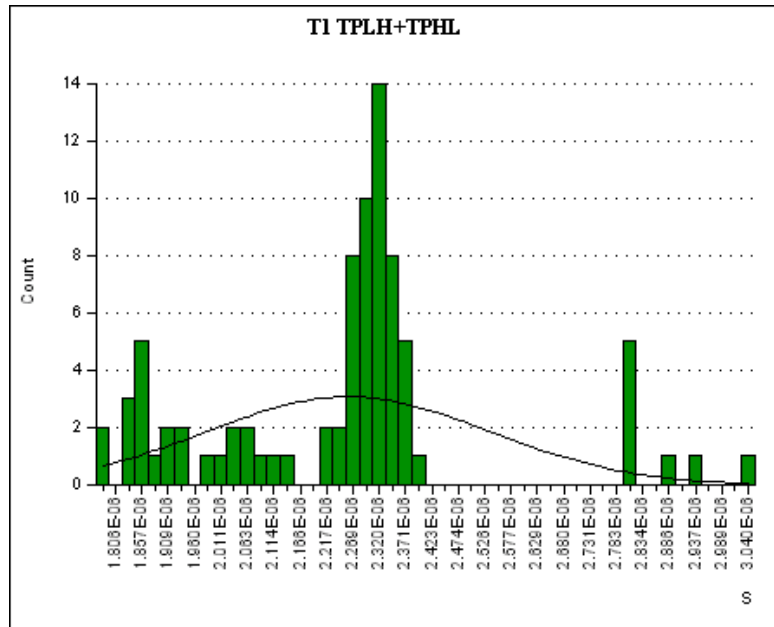
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=9.015, Test.Name=T1 TPLH+TPHL



Statistics: (S)

Max	3.040E-06	25%	2.070E-06	SpecHigh	N/A
Mean	2.256E-06	10%	1.860E-06	SpecLow	N/A
Min	1.780E-06	N	82	PctWithinSpec	N/A
Range	1.260E-06	Cp	N/A	c	
StdDev	272.678E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8777	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	2.410E-06	Skew	0.5638		
75%	2.340E-06	Kurtosis	0.8661		
Median	2.300E-06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T		0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T		0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T		0

Data: Raw Data

Stat limits applied

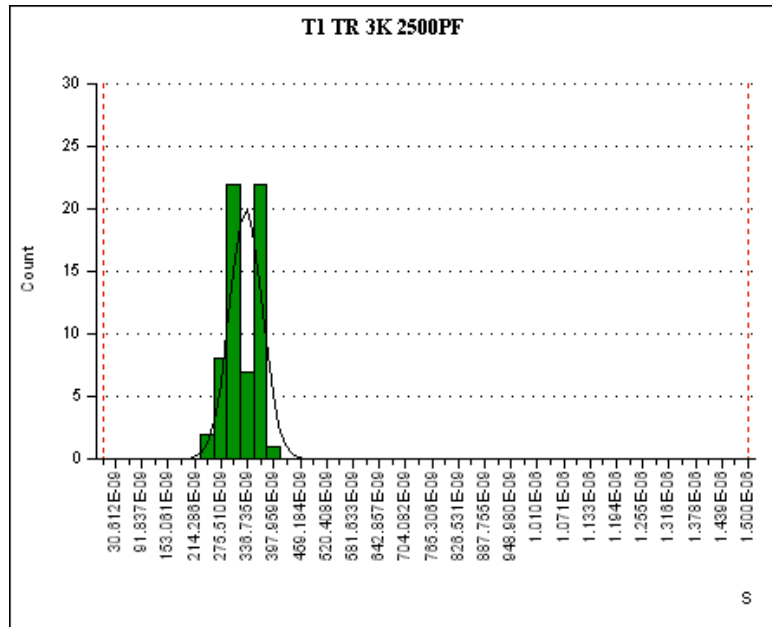
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=10.000, Test.Name=T1 TR 3K 2500PF



Statistics: (S)

Max	390.000E-09	25%	300.000E-09	SpecHigh	1.500E-06
Mean	328.548E-09	10%	280.000E-09	SpecLow	0
Min	240.000E-09	N	62	PctWithinSpec	100.00
Range	150.000E-09	Cp	>4.0000	PctDefSpec	0
StdDev	37.802E-09	Cpl	2.8971	NWithinSpec	62
W	0.9219	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0007	Cpk	2.8971		
90%	370.000E-09	Skew	-0.2713		
75%	360.000E-09	Kurtosis	-0.8790		
Median	315.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

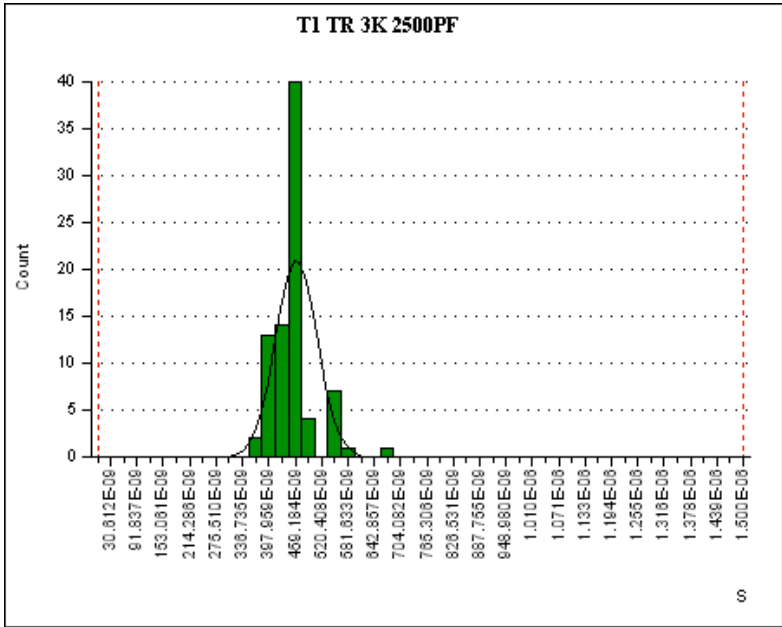
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=10.000, Test.Name=T1 TR 3K 2500PF



Statistics: (S)

Max	679.999E-09	25%	430.000E-09	SpecHigh	1.500E-06
Mean	456.585E-09	10%	400.000E-09	SpecLow	0
Min	380.000E-09	N	82	PctWithinSpec	100.00
Range	300.000E-09	Cp	>4.0000	c	
StdDev	47.485E-09	Cpl	3.2051	PctDefSpec	0
W	0.8535	Cpu	>4.0000	NWithinSpec	82
WpValue	0.0000	Cpk	3.2051	NOutsideSpec	0
90%	540.000E-09	Skew	1.6704		
75%	470.000E-09	Kurtosis	5.5000		
Median	455.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

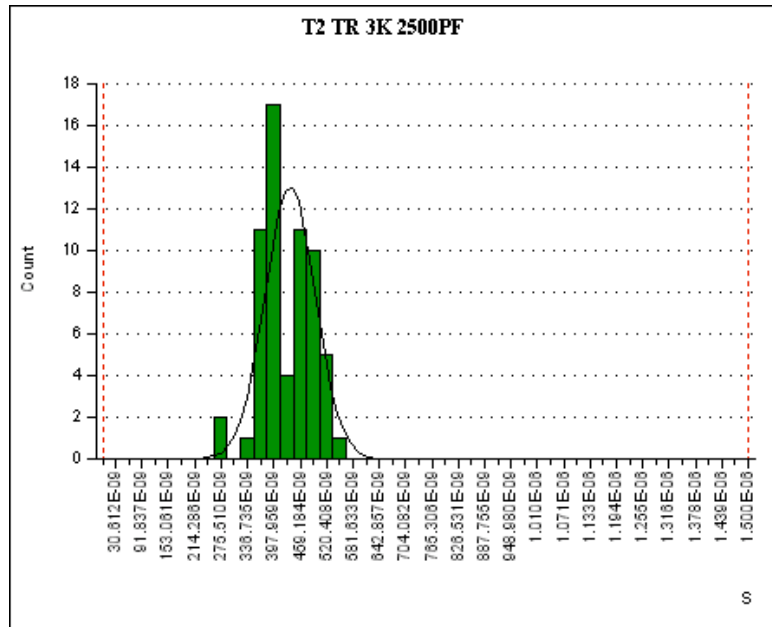
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=10.001, Test.Name=T2 TR 3K 2500PF



Statistics: (S)

Max	539.999E-09	25%	390.000E-09	SpecHigh	1.500E-06
Mean	430.483E-09	10%	369.999E-09	SpecLow	0
Min	280.000E-09	N	62	PctWithinSpec	100.00
Range	260.000E-09	Cp	>4.0000	PctDefSpec	0
StdDev	57.955E-09	Cpl	2.4760	NWithinSpec	62
W	0.9641	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0669	Cpk	2.4760		
90%	500.000E-09	Skew	-0.2663		
75%	480.000E-09	Kurtosis	-0.1791		
Median	419.999E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

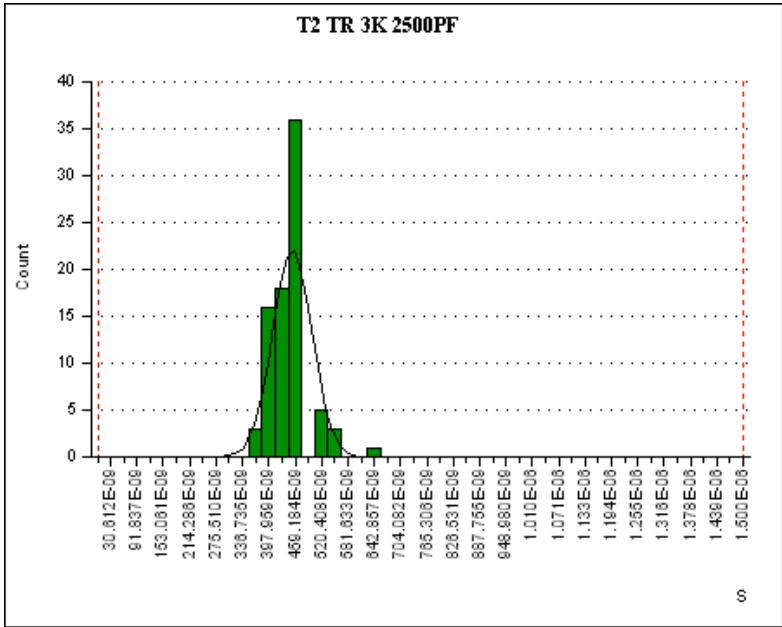
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=10.001, Test.Name=T2 TR 3K 2500PF



Statistics: (S)

Max	639.999E-09	25%	420.000E-09	SpecHigh	1.500E-06
Mean	447.073E-09	10%	390.000E-09	SpecLow	0
Min	370.000E-09	N	82	PctWithinSpec	100.00
Range	270.000E-09	Cp	>4.0000	c	
StdDev	45.528E-09	Cpl	3.2732	PctDefSpec	0
W	0.8737	Cpu	>4.0000	NWithinSpec	82
WpValue	0.0000	Cpk	3.2732	NOutsideSpec	0
90%	530.000E-09	Skew	1.3718		
75%	460.000E-09	Kurtosis	3.5708		
Median	450.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

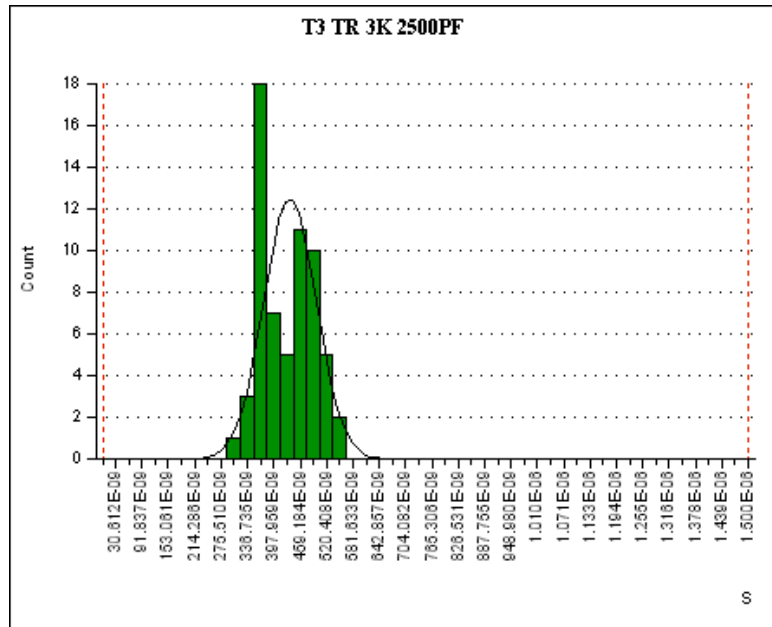
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=10.002, Test.Name=T3 TR 3K 2500PF



Statistics: (S)

Max	549.999E-09	25%	380.000E-09	SpecHigh	1.500E-06
Mean	430.161E-09	10%	360.000E-09	SpecLow	0
Min	300.000E-09	N	62	PctWithinSpec	100.00
Range	250.000E-09	Cp	>4.0000	c	
StdDev	60.611E-09	Cpl	2.3657	PctDefSpec	0
W	0.9550	Cpu	>4.0000	NWithinSpec	62
WpValue	0.0233	Cpk	2.3657	NOutsideSpec	0
90%	509.999E-09	Skew	0.1210		
75%	480.000E-09	Kurtosis	-1.0236		
Median	429.999E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

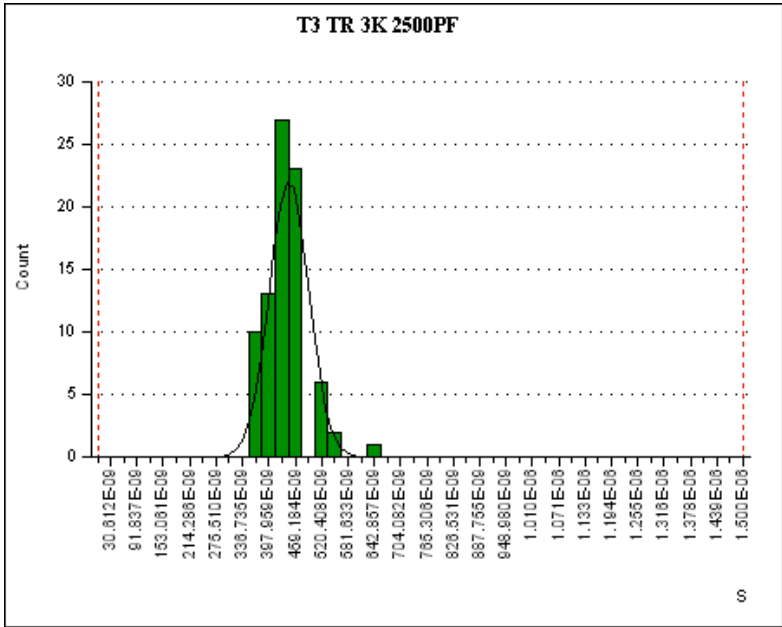
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=10.002, Test.Name=T3 TR 3K 2500PF



Statistics: (S)

Max	639.999E-09	25%	410.000E-09	SpecHigh	1.500E-06
Mean	439.512E-09	10%	380.000E-09	SpecLow	0
Min	370.000E-09	N	82	PctWithinSpec	100.00
Range	270.000E-09	Cp	>4.0000	c	
StdDev	45.376E-09	Cpl	3.2286	PctDefSpec	0
W	0.8582	Cpu	>4.0000	NWithinSpec	82
WpValue	0.0000	Cpk	3.2286	NOutsideSpec	0
90%	510.000E-09	Skew	1.4132		
75%	450.000E-09	Kurtosis	4.2816		
Median	440.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

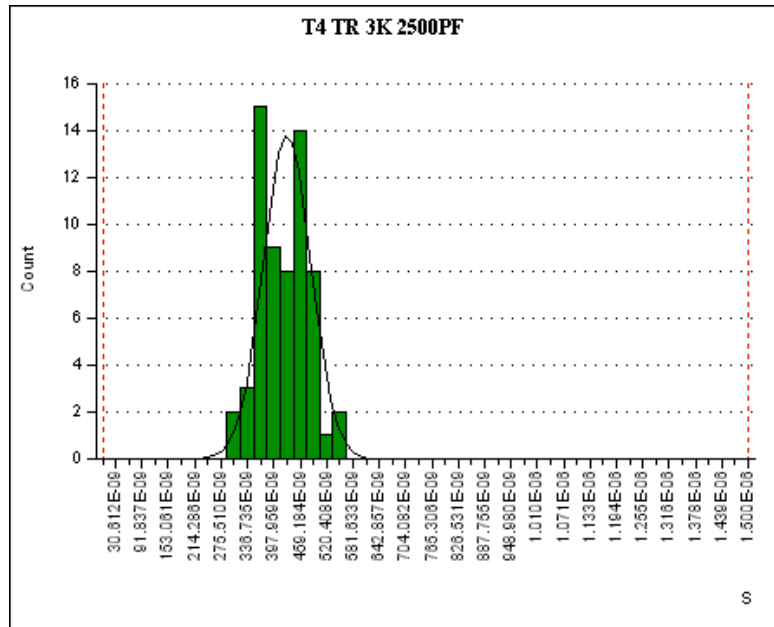
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=10.003, Test.Name=T4 TR 3K 2500PF



Statistics: (S)

Max	539.999E-09	25%	369.999E-09	SpecHigh	1.500E-06
Mean	423.387E-09	10%	360.000E-09	SpecLow	0
Min	320.000E-09	N	62	PctWithinSpec	100.00
Range	220.000E-09	Cp	>4.0000	PctDefSpec	0
StdDev	54.980E-09	Cpl	2.5669	NWithinSpec	62
W	0.9690	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.1179	Cpk	2.5669		
90%	490.000E-09	Skew	0.0696		
75%	470.000E-09	Kurtosis	-0.8485		
Median	419.999E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

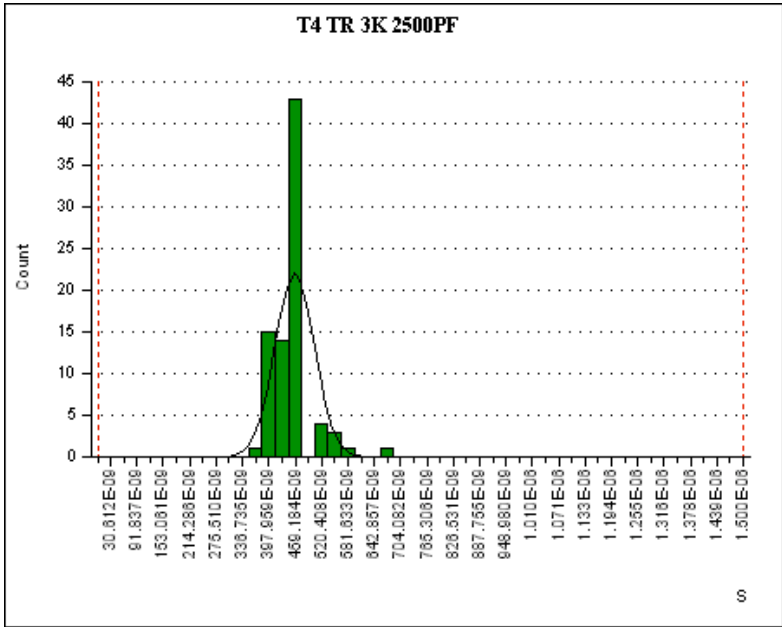
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=10.003, Test.Name=T4 TR 3K 2500PF



Statistics: (S)

Max	659.999E-09	25%	430.000E-09	SpecHigh	1.500E-06
Mean	452.561E-09	10%	400.000E-09	SpecLow	0
Min	380.000E-09	N	82	PctWithinSpec	100.00
Range	280.000E-09	Cp	>4.0000	c	
StdDev	45.292E-09	Cpl	3.3307	PctDefSpec	0
W	0.8424	Cpu	>4.0000	NWithinSpec	82
WpValue	0.0000	Cpk	3.3307	NOutsideSpec	0
90%	530.000E-09	Skew	1.6454		
75%	460.000E-09	Kurtosis	5.1141		
Median	450.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

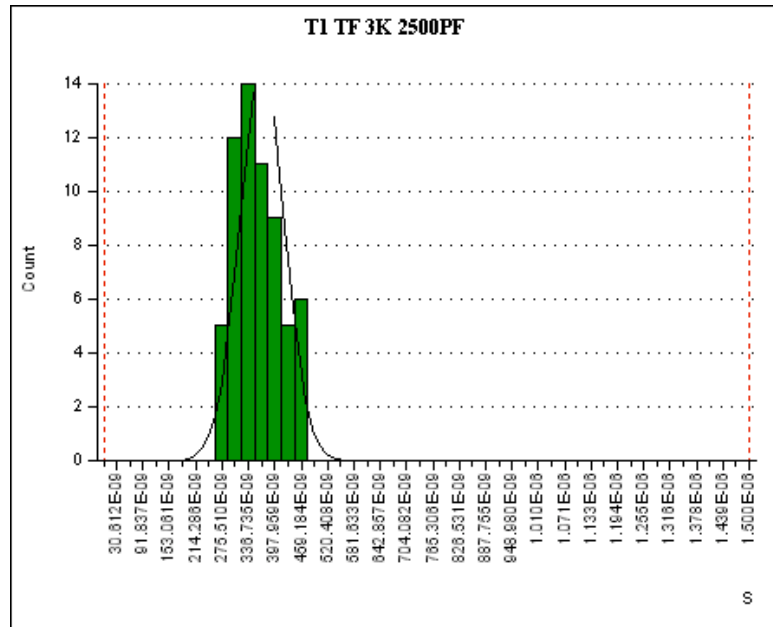
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=10.004, Test.Name=T1 TF 3K 2500PF



Statistics: (S)

Max	470.000E-09	25%	320.000E-09	SpecHigh	1.500E-06
Mean	363.387E-09	10%	310.000E-09	SpecLow	0
Min	270.000E-09	N	62	PctWithinSpec	100.00
Range	200.000E-09	Cp	>4.0000	PctDefSpec	0
StdDev	52.070E-09	Cpl	2.3263	NWithinSpec	62
W	0.9576	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0314	Cpk	2.3263		
90%	430.000E-09	Skew	0.3729		
75%	400.000E-09	Kurtosis	-0.6821		
Median	355.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

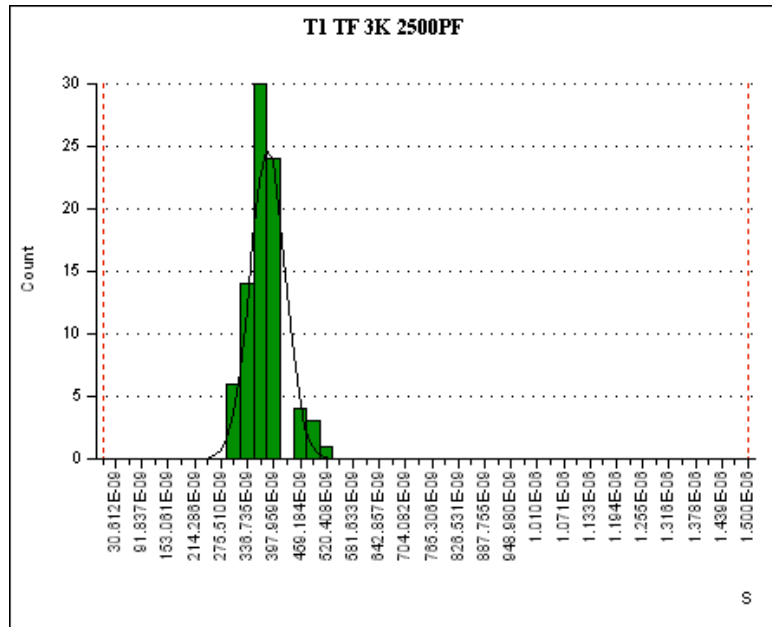
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=10.004, Test.Name=T1 TF 3K 2500PF



Statistics: (S)

Max	510.000E-09	25%	360.000E-09	SpecHigh	1.500E-06
Mean	378.902E-09	10%	330.000E-09	SpecLow	0
Min	310.000E-09	N	82	PctWithinSpec	100.00
Range	200.000E-09	Cp	>4.0000	PctDefSpec	0
StdDev	40.308E-09	Cpl	3.1334	NWithinSpec	82
W	0.8911	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	3.1334		
90%	410.000E-09	Skew	1.0107		
75%	390.000E-09	Kurtosis	1.8321		
Median	380.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

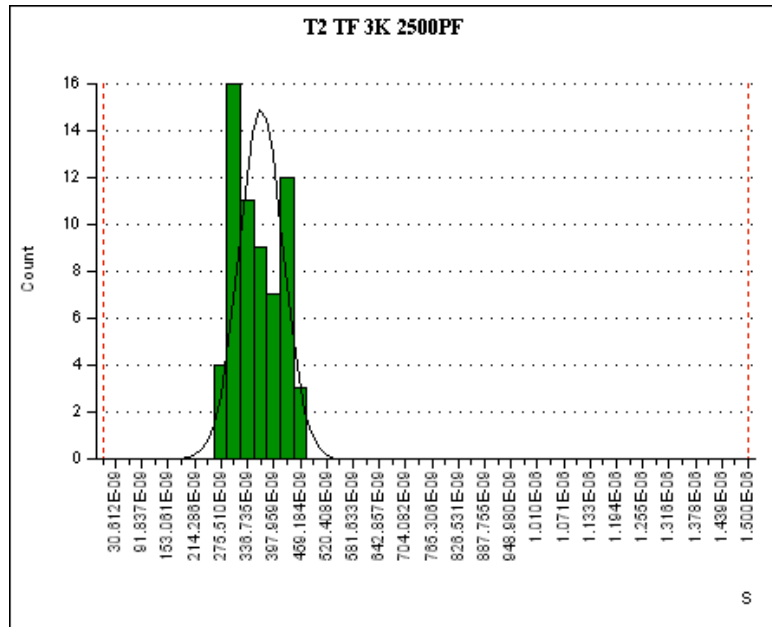
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=10.005, Test.Name=T2 TF 3K 2500PF



Statistics: (S)

Max	460.000E-09	25%	320.000E-09	SpecHigh	1.500E-06
Mean	363.548E-09	10%	310.000E-09	SpecLow	0
Min	280.000E-09	N	62	PctWithinSpec	100.00
Range	180.000E-09	Cp	>4.0000	PctDefSpec	0
StdDev	50.768E-09	Cpl	2.3870	NWithinSpec	62
W	0.9231	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0008	Cpk	2.3870		
90%	430.000E-09	Skew	0.2884		
75%	410.000E-09	Kurtosis	-1.1725		
Median	355.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

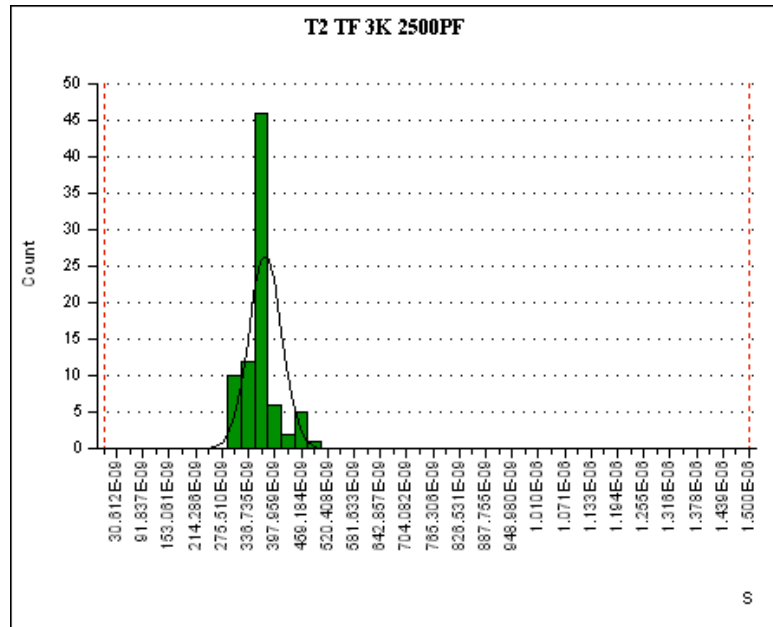
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=10.005, Test.Name=T2 TF 3K 2500PF



Statistics: (S)

Max	490.000E-09	25%	340.000E-09	SpecHigh	1.500E-06
Mean	370.609E-09	10%	320.000E-09	SpecLow	0
Min	300.000E-09	N	82	PctWithinSpec	100.00
Range	190.000E-09	Cp	>4.0000	c	
StdDev	37.593E-09	Cpl	3.2862	PctDefSpec	0
W	0.8939	Cpu	>4.0000	NWithinSpec	82
WpValue	0.0000	Cpk	3.2862	NOutsideSpec	0
90%	400.000E-09	Skew	0.8345		
75%	380.000E-09	Kurtosis	1.5381		
Median	370.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

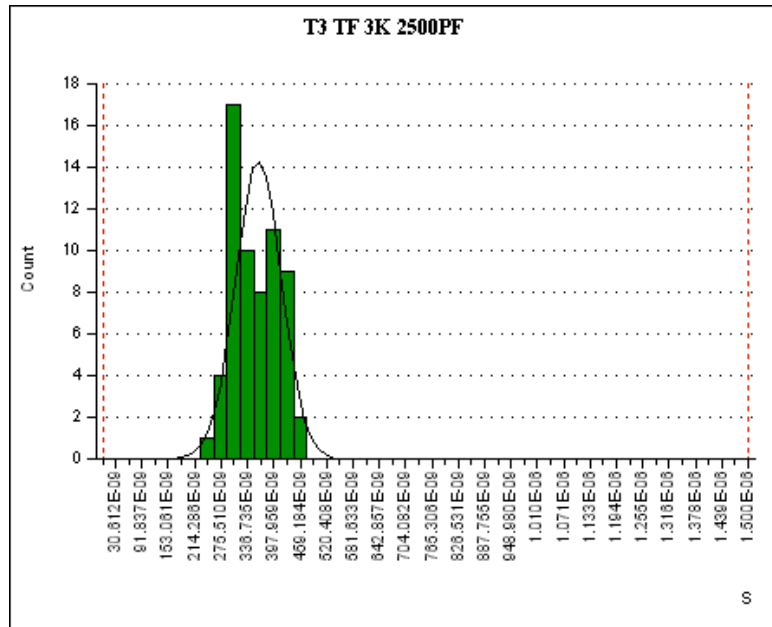
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=10.006, Test.Name=T3 TF 3K 2500PF



Statistics: (S)

Max	460.000E-09	25%	310.000E-09	SpecHigh	1.500E-06
Mean	357.419E-09	10%	300.000E-09	SpecLow	0
Min	260.000E-09	N	62	PctWithinSpec	100.00
Range	200.000E-09	Cp	>4.0000	PctDefSpec	0
StdDev	53.006E-09	Cpl	2.2477	NWithinSpec	62
W	0.9429	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0062	Cpk	2.2477		
90%	420.000E-09	Skew	0.1485		
75%	410.000E-09	Kurtosis	-1.2414		
Median	350.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

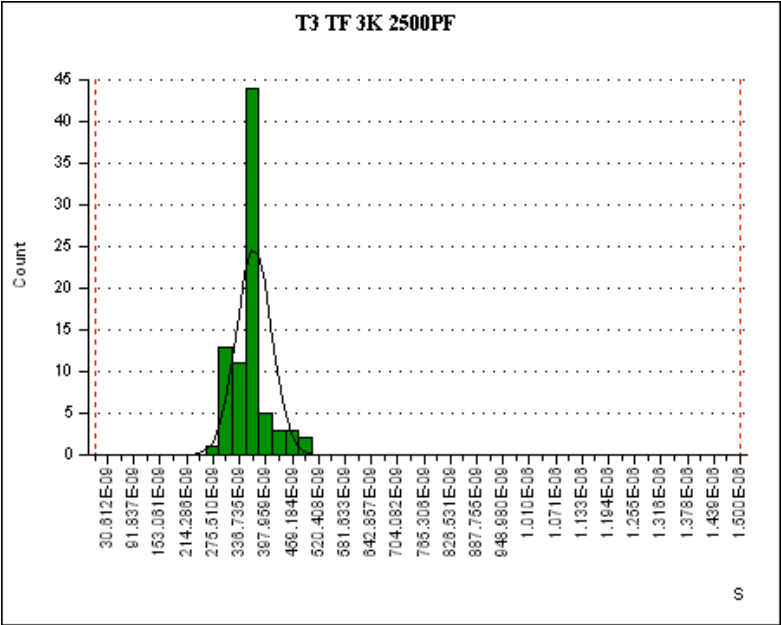
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=10.006, Test.Name=T3 TF 3K 2500PF



Statistics: (S)

Max	490.000E-09	25%	340.000E-09	SpecHigh	1.500E-06
Mean	365.366E-09	10%	310.000E-09	SpecLow	0
Min	290.000E-09	N	82	PctWithinSpec	100.00
Range	200.000E-09	Cp	>4.0000	c	
StdDev	40.344E-09	Cpl	3.0187	PctDefSpec	0
W	0.9105	Cpu	>4.0000	NWithinSpec	82
WpValue	0.0000	Cpk	3.0187	NOutsideSpec	0
90%	400.000E-09	Skew	0.8157		
75%	380.000E-09	Kurtosis	1.3651		
Median	370.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

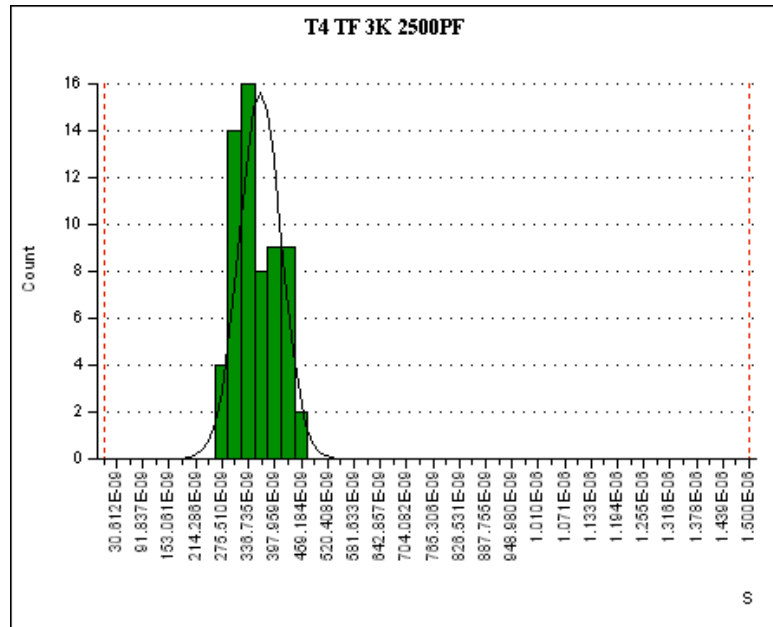
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=10.007, Test.Name=T4 TF 3K 2500PF



Statistics: (S)

Max	460.000E-09	25%	320.000E-09	SpecHigh	1.500E-06
Mean	359.354E-09	10%	300.000E-09	SpecLow	0
Min	270.000E-09	N	62	PctWithinSpec	100.00
Range	190.000E-09	Cp	>4.0000	c	
StdDev	48.447E-09	Cpl	2.4725	PctDefSpec	0
W	0.9601	Cpu	>4.0000	NWithinSpec	62
WpValue	0.0420	Cpk	2.4725	NOutsideSpec	0
90%	430.000E-09	Skew	0.2409		
75%	400.000E-09	Kurtosis	-0.9315		
Median	350.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

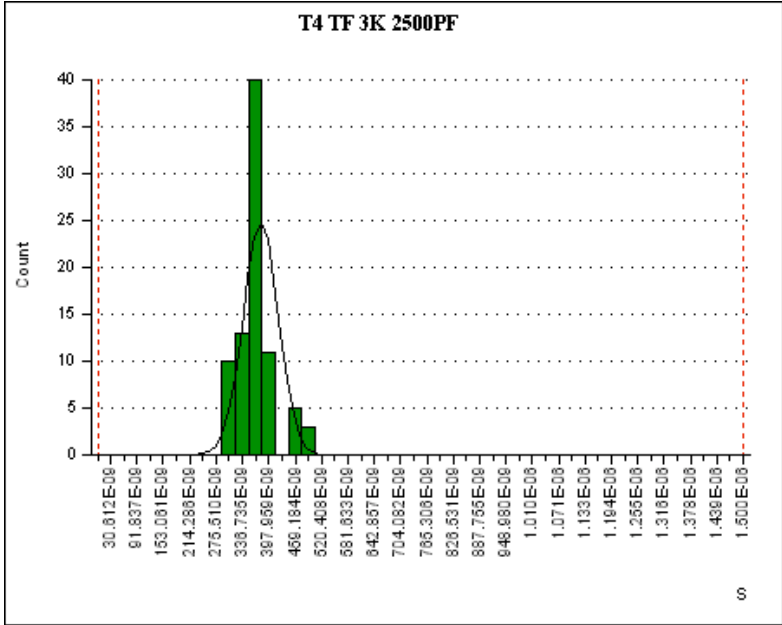
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=10.007, Test.Name=T4 TF 3K 2500PF



Statistics: (S)

Max	500.000E-09	25%	350.000E-09	SpecHigh	1.500E-06
Mean	374.268E-09	10%	320.000E-09	SpecLow	0
Min	310.000E-09	N	82	PctWithinSpec	100.00
Range	190.000E-09	Cp	>4.0000	c	
StdDev	40.278E-09	Cpl	3.0974	PctDefSpec	0
W	0.8797	Cpu	>4.0000	NWithinSpec	82
WpValue	0.0000	Cpk	3.0974	NOutsideSpec	0
90%	410.000E-09	Skew	1.0310		
75%	380.000E-09	Kurtosis	1.8457		
Median	380.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

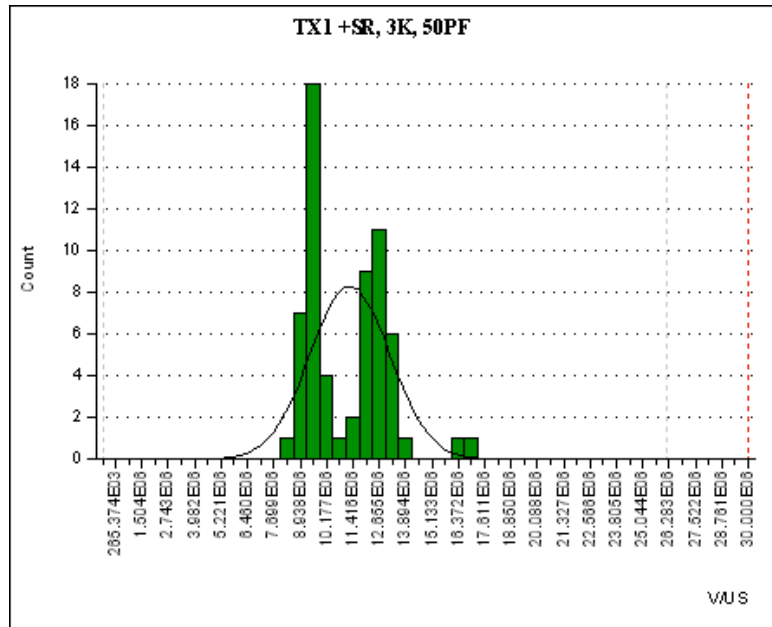
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=11.000, Test.Name=TX1 +SR, 3K, 50PF



Statistics: (V/US)

Max	17.143E06	25%	9.524E06	SpecHigh	30.000E06
Mean	11.133E06	10%	9.231E06	SpecLow	N/A
Min	8.451E06	N	62	PctWithinSpec	100.00
Range	8.692E06	Cp	N/A	c	
StdDev	1.848E06	Cpl	N/A	PctDefSpec	0
W	0.8872	Cpu	3.4037	NWithinSpec	62
WpValue	0.0000	Cpk	3.4037	NOutsideSpec	0
90%	13.043E06	Skew	0.7916		
75%	12.500E06	Kurtosis	0.6737		
Median	11.010E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

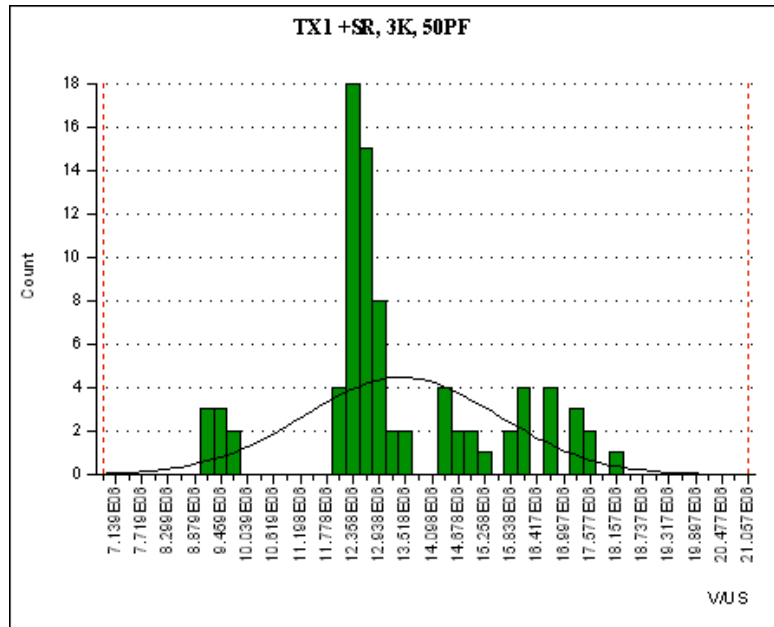
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
26.170E06	-354.097E03	100.00	0	62	0

Plot limits applied

NOutsidePlot

0

Test.Number=11.000, Test.Name=TX1 +SR, 3K, 50PF



Statistics: (V/US)

Max	18.182E06	25%	12.500E06	SpecHigh	21.057E06
Mean	13.364E06	10%	12.000E06	SpecLow	6.849E06
Min	9.091E06	N	82	PctWithinSpec	100.00
Range	9.091E06	Cp	1.1185	c	
StdDev	2.117E06	Cpl	1.0258	PctDefSpec	0
W	0.9156	Cpu	1.2111	NWithinSpec	82
WpValue	0.0000	Cpk	1.0258	NOutsideSpec	0
90%	16.667E06	Skew	0.2560		
75%	14.634E06	Kurtosis	-0.0125		
Median	12.766E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

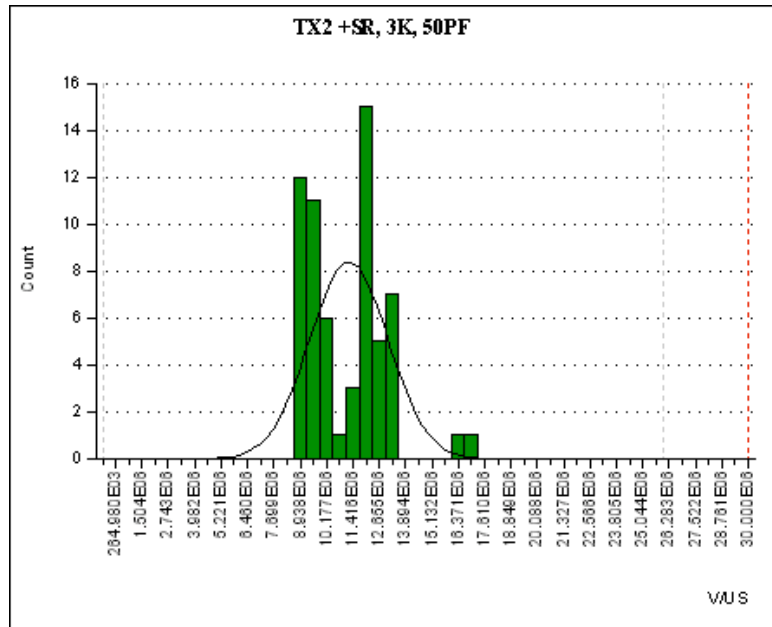
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=11.001, Test.Name=TX2 +SR, 3K, 50PF



Statistics: (V/US)

Max	17.143E06	25%	9.375E06	SpecHigh	30.000E06
Mean	11.089E06	10%	9.091E06	SpecLow	N/A
Min	8.696E06	N	62	PctWithinSpec	100.00
Range	8.447E06	Cp	N/A	PctDefSpec	0
StdDev	1.826E06	Cpl	N/A	NWithinSpec	62
W	0.8818	Cpu	3.4528	NOutsideSpec	0
WpValue	0.0000	Cpk	3.4528		
90%	13.043E06	Skew	0.9296		
75%	12.245E06	Kurtosis	1.3177		
Median	11.216E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

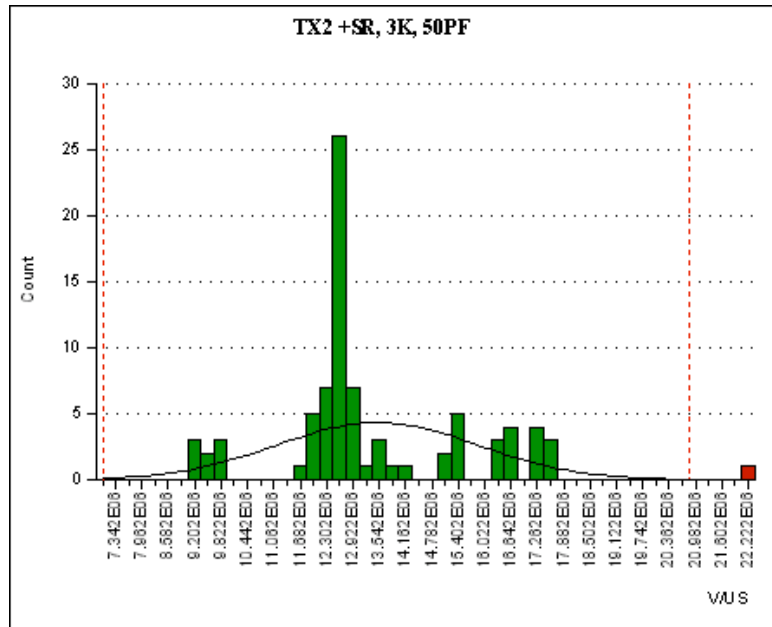
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
26.004E06	-354.500E03	100.00	0	62	0

Plot limits applied

NOutsidePlot

0

Test.Number=11.001, Test.Name=TX2 +SR, 3K, 50PF



Statistics: (V/US)

Max	22.222E06	25%	12.245E06	SpecHigh	20.841E06
Mean	13.439E06	10%	11.765E06	SpecLow	7.032E06
Min	9.091E06	N	82	PctWithinSpec	98.78
Range	13.131E06	Cp	0.9833	c	
StdDev	2.341E06	Cpl	0.9124	PctDefSpec	1.22
W	0.9003	Cpu	1.0541	NWithinSpec	81
WpValue	0.0000	Cpk	0.9124	NOutsideSpec	1
90%	16.667E06	Skew	0.7735		
75%	15.000E06	Kurtosis	1.5364		
Median	12.766E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

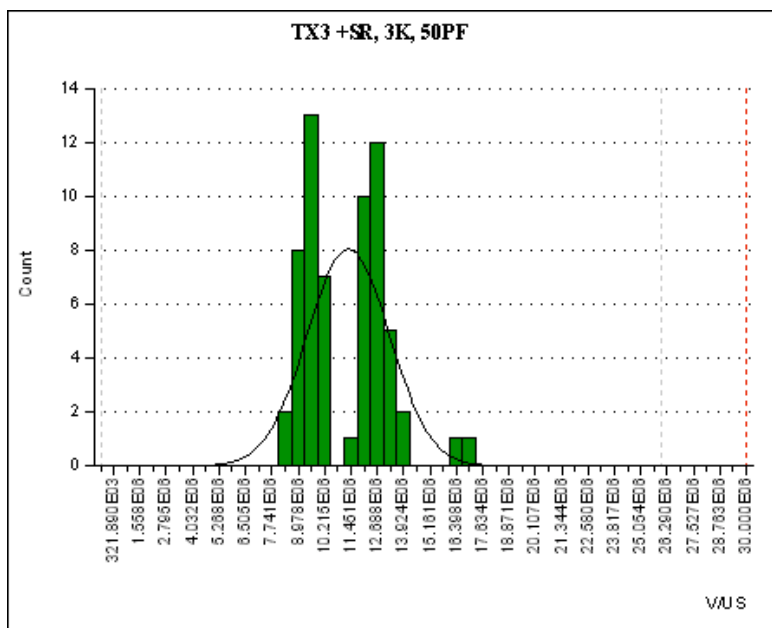
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=11.002, Test.Name=TX3 +SR, 3K, 50PF



Statistics: (V/US)

Max	17.143E06	25%	9.524E06	SpecHigh	30.000E06
Mean	11.189E06	10%	9.091E06	SpecLow	N/A
Min	8.219E06	N	62	PctWithinSpec	100.00
Range	8.924E06	Cp	N/A	c	
StdDev	1.900E06	Cpl	N/A	PctDefSpec	0
W	0.9027	Cpu	3.3001	NWithinSpec	62
WpValue	0.0001	Cpk	3.3001	NOutsideSpec	0
90%	13.043E06	Skew	0.7181		
75%	12.500E06	Kurtosis	0.6586		
Median	11.652E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

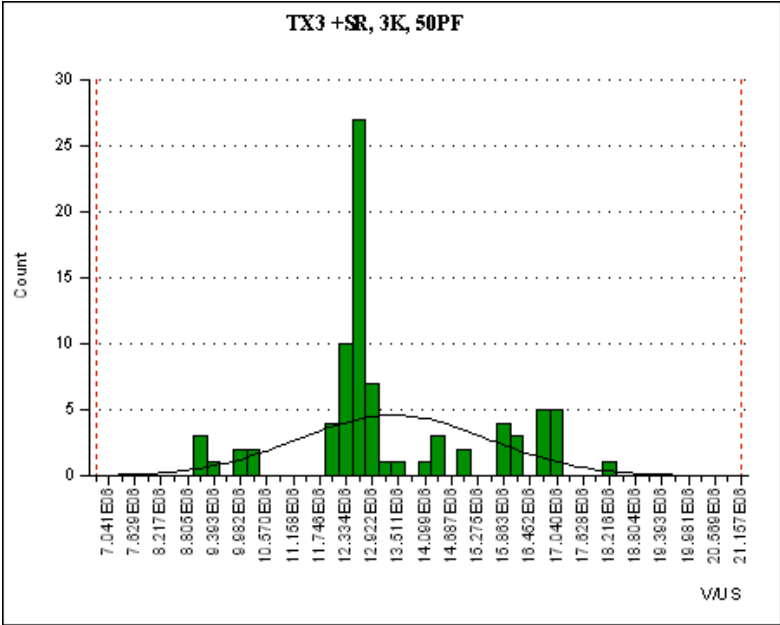
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
26.001E06	-296.404E03	100.00	0	62	0

Plot limits applied

NOutsidePlot

0

Test.Number=11.002, Test.Name=TX3 +SR, 3K, 50PF



Statistics: (V/US)

Max	18.182E06	25%	12.245E06	SpecHigh	21.157E06
Mean	13.322E06	10%	12.000E06	SpecLow	6.746E06
Min	8.955E06	N	82	PctWithinSpec	100.00
Range	9.227E06	Cp	1.1457	c	
StdDev	2.096E06	Cpl	1.0455	PctDefSpec	0
W	0.8994	Cpu	1.2459	NWithinSpec	82
WpValue	0.0000	Cpk	1.0455	NOutsideSpec	0
90%	16.667E06	Skew	0.3615		
75%	14.286E06	Kurtosis	-0.1265		
Median	12.766E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

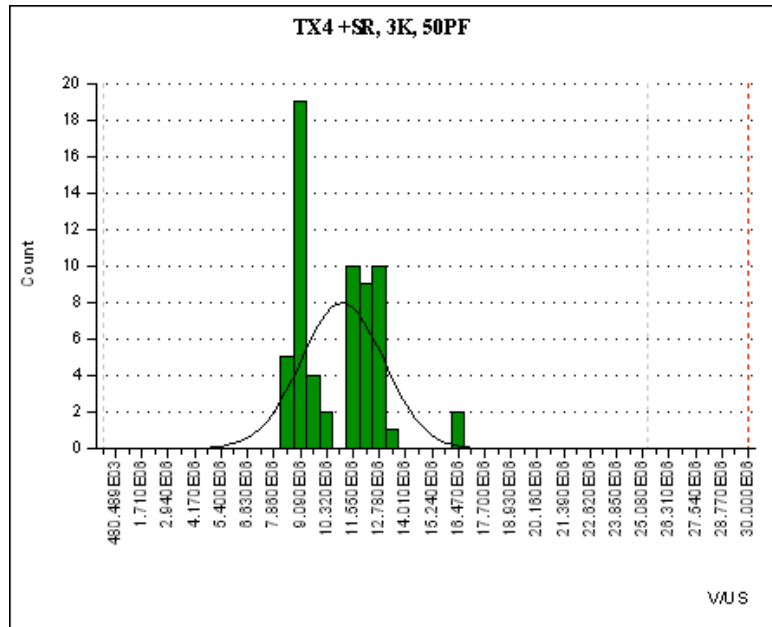
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=11.003, Test.Name=TX4 +SR, 3K, 50PF



Statistics: (V/US)

Max	16.667E06	25%	9.231E06	SpecHigh	30.000E06
Mean	10.921E06	10%	8.824E06	SpecLow	N/A
Min	8.571E06	N	62	PctWithinSpec	100.00
Range	8.095E06	Cp	N/A	PctDefSpec	0
StdDev	1.903E06	Cpl	N/A	NWithinSpec	62
W	0.8783	Cpu	3.3423	NOutsideSpec	0
WpValue	0.0000	Cpk	3.3423		
90%	13.043E06	Skew	0.7558		
75%	12.245E06	Kurtosis	0.6113		
Median	11.538E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

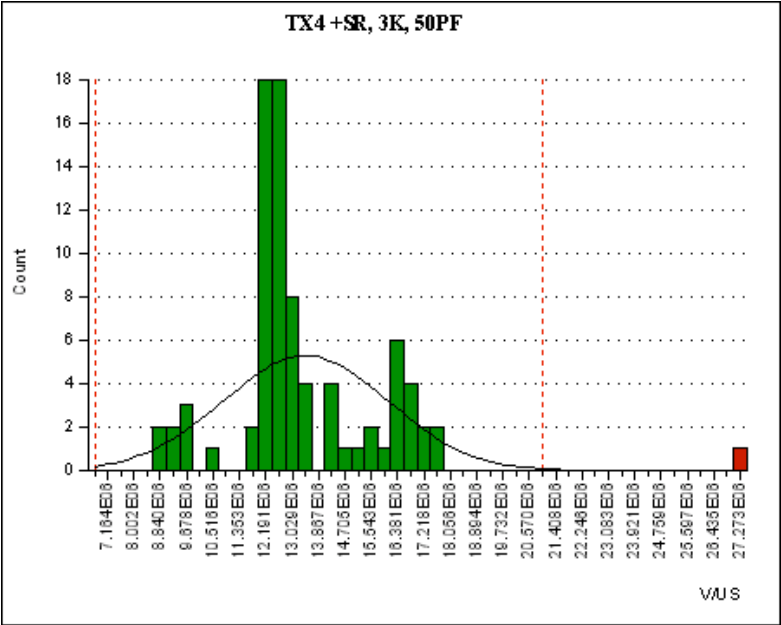
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
25.316E06	-134.501E03	100.00	0	62	0

Plot limits applied

NOutsidePlot

0

Test.Number=11.003, Test.Name=TX4 +SR, 3K, 50PF



Statistics: (V/US)

Max	27.273E06	25%	12.245E06	SpecHigh	20.962E06
Mean	13.376E06	10%	11.765E06	SpecLow	6.745E06
Min	8.824E06	N	82	PctWithinSpec	98.78
Range	18.449E06	Cp	0.9150	c	
StdDev	2.589E06	Cpl	0.8536	PctDefSpec	1.22
W	0.8276	Cpu	0.9765	NWithinSpec	81
WpValue	0.0000	Cpk	0.8536	NOutsideSpec	1
90%	16.667E06	Skew	1.9648		
75%	14.286E06	Kurtosis	9.1527		
Median	12.766E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

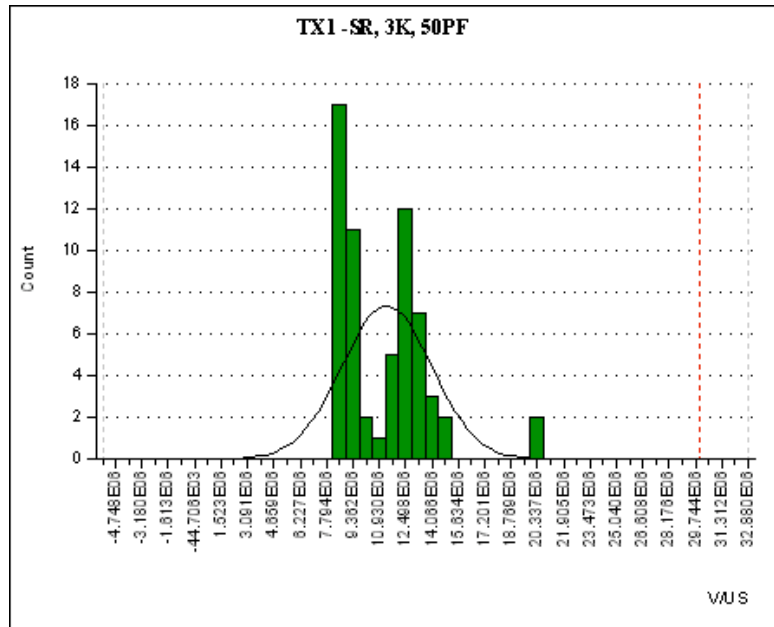
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=11.004, Test.Name=TX1 -SR, 3K, 50PF



Statistics: (V/US)

Max	20.690E06	25%	8.955E06	SpecHigh	30.000E06
Mean	11.175E06	10%	8.571E06	SpecLow	N/A
Min	8.219E06	N	62	PctWithinSpec	100.00
Range	12.470E06	Cp	N/A	PctDefSpec	0
StdDev	2.630E06	Cpl	N/A	NWithinSpec	62
W	0.8477	Cpu	2.3860	NOutsideSpec	0
WpValue	0.0000	Cpk	2.3860		
90%	13.954E06	Skew	1.3308		
75%	12.766E06	Kurtosis	2.8504		
Median	11.325E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

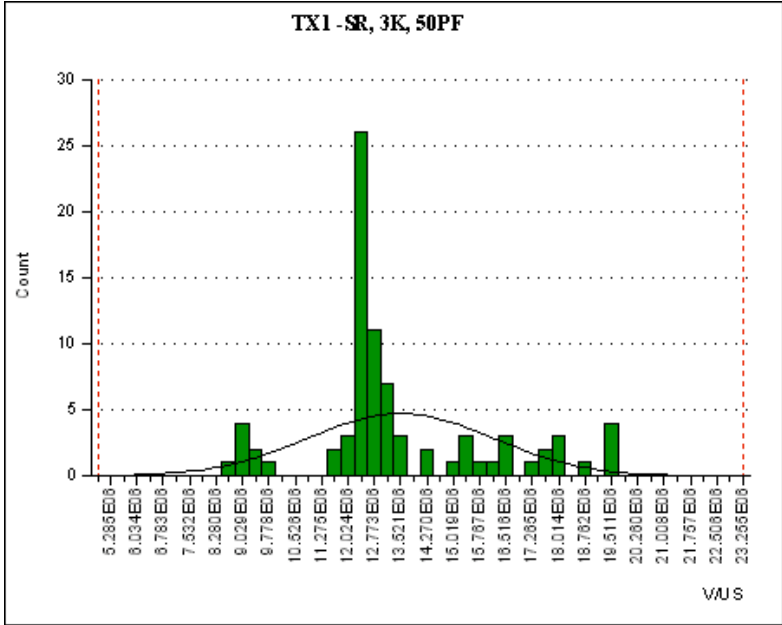
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
32.880E06	-5.532E06	100.00	0	62	0

Plot limits applied

NOutsidePlot

0

Test.Number=11.004, Test.Name=TX1 -SR, 3K, 50PF



Statistics: (V/US)

Max	19.355E06	25%	12.245E06	SpecHigh	23.255E06
Mean	13.433E06	10%	11.765E06	SpecLow	4.911E06
Min	8.824E06	N	82	PctWithinSpec	100.00
Range	10.531E06	Cp	1.1838	PctDefSpec	0
StdDev	2.583E06	Cpl	1.0999	NWithinSpec	82
W	0.8754	Cpu	1.2676	NOutsideSpec	0
WpValue	0.0000	Cpk	1.0999		
90%	17.647E06	Skew	0.7263		
75%	14.286E06	Kurtosis	0.2508		
Median	12.766E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

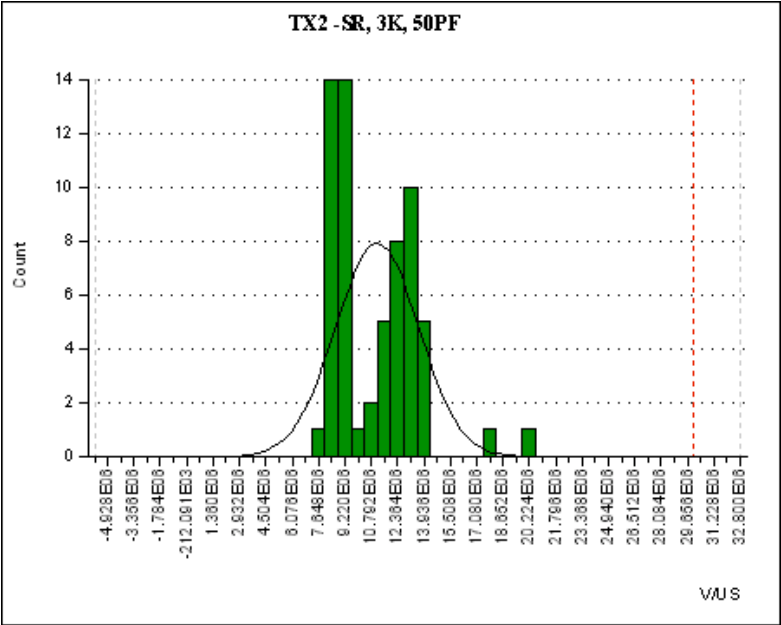
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=11.005, Test.Name=TX2 -SR, 3K, 50PF



Statistics: (V/US)

Max	20.000E06	25%	8.955E06	SpecHigh	30.000E06
Mean	10.945E06	10%	8.451E06	SpecLow	N/A
Min	7.895E06	N	62	PctWithinSpec	100.00
Range	12.105E06	Cp	N/A	c	
StdDev	2.444E06	Cpl	N/A	PctDefSpec	0
W	0.8588	Cpu	2.5993	NWithinSpec	62
WpValue	0.0000	Cpk	2.5993	NOutsideSpec	0
90%	13.636E06	Skew	1.1885		
75%	12.766E06	Kurtosis	2.2560		
Median	10.819E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01.AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01.AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01.AT	-	0

Data: Raw Data

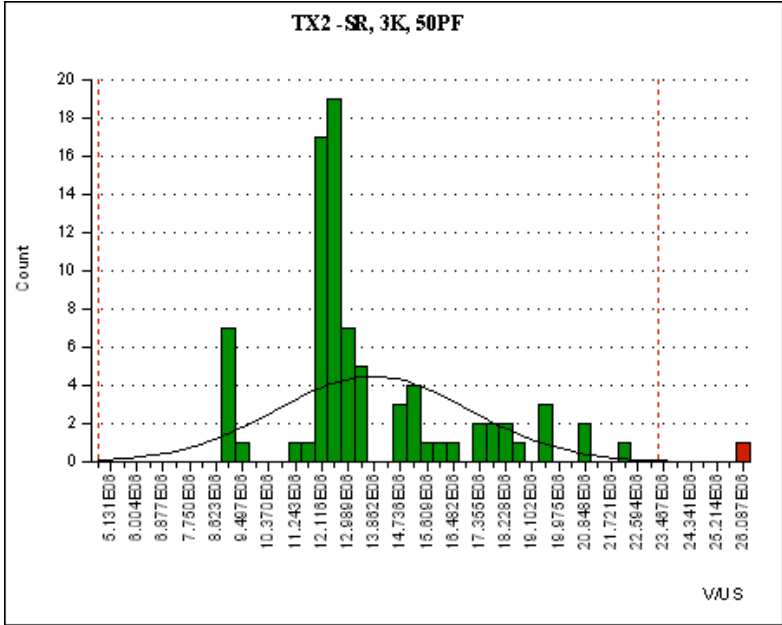
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
32.800E06	-5.714E06	100.00	0	62	0

Plot limits applied

NOutsidePlot
0

Test.Number=11.005, Test.Name=TX2 -SR, 3K, 50PF



Statistics: (V/US)

Max	26.087E06	25%	12.245E06	SpecHigh	23.263E06
Mean	13.723E06	10%	11.321E06	SpecLow	4.694E06
Min	8.955E06	N	82	PctWithinSpec	98.78
Range	17.132E06	Cp	0.9722	c	
StdDev	3.183E06	Cpl	0.9454	PctDefSpec	1.22
W	0.8610	Cpu	0.9989	NWithinSpec	81
WpValue	0.0000	Cpk	0.9454	NOutsideSpec	1
90%	18.182E06	Skew	1.3197		
75%	15.000E06	Kurtosis	2.3970		
Median	12.766E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

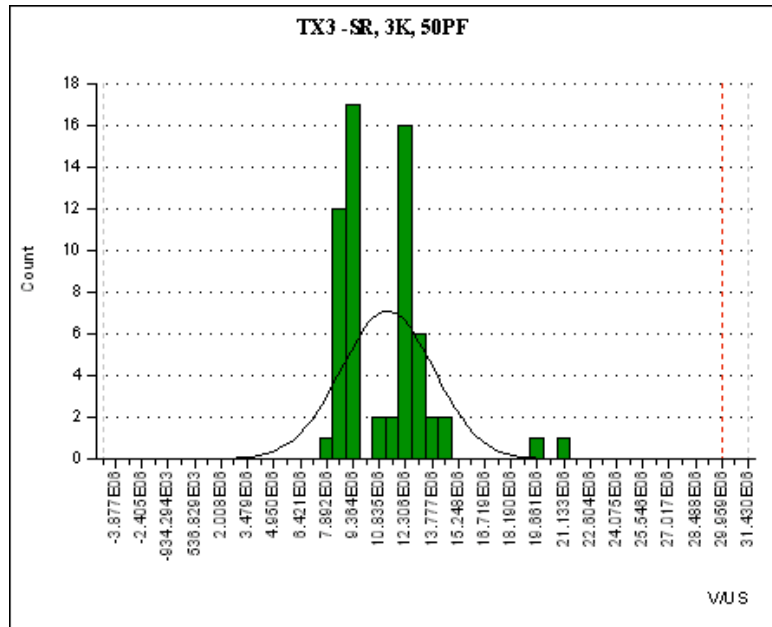
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=11.006, Test.Name=TX3 -SR, 3K, 50PF



Statistics: (V/US)

Max	21.429E06	25%	9.091E06	SpecHigh	30.000E06
Mean	11.103E06	10%	8.824E06	SpecLow	N/A
Min	8.219E06	N	62	PctWithinSpec	100.00
Range	13.209E06	Cp	N/A	PctDefSpec	0
StdDev	2.562E06	Cpl	N/A	NWithinSpec	62
W	0.8098	Cpu	2.4591	NOutsideSpec	0
WpValue	0.0000	Cpk	2.4591		
90%	13.333E06	Skew	1.7012		
75%	12.500E06	Kurtosis	4.7193		
Median	11.111E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

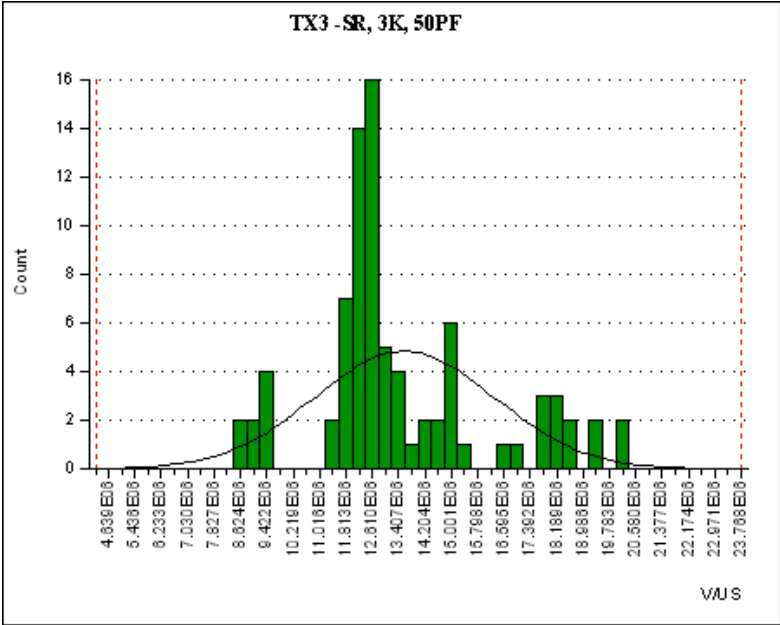
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
31.430E06	-4.612E06	100.00	0	62	0

Plot limits applied

NOutsidePlot

0

Test.Number=11.006, Test.Name=TX3 -SR, 3K, 50PF



Statistics: (V/US)

Max	20.000E06	25%	12.245E06	SpecHigh	23.768E06
Mean	13.485E06	10%	11.538E06	SpecLow	4.241E06
Min	8.696E06	N	82	PctWithinSpec	100.00
Range	11.304E06	Cp	1.2087	c	
StdDev	2.693E06	Cpl	1.1443	PctDefSpec	0
W	0.8929	Cpu	1.2730	NWithinSpec	82
WpValue	0.0000	Cpk	1.1443	NOutsideSpec	0
90%	18.182E06	Skew	0.7277		
75%	15.000E06	Kurtosis	0.2692		
Median	12.633E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

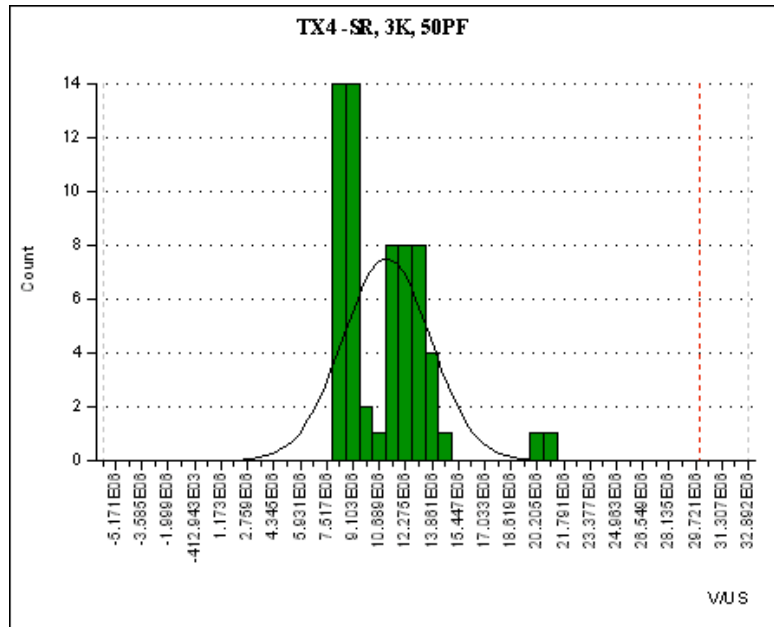
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=11.007, Test.Name=TX4 -SR, 3K, 50PF



Statistics: (V/US)

Max	20.690E06	25%	8.824E06	SpecHigh	30.000E06
Mean	10.938E06	10%	8.451E06	SpecLow	N/A
Min	8.108E06	N	62	PctWithinSpec	100.00
Range	12.582E06	Cp	N/A	c	
StdDev	2.604E06	Cpl	N/A	PctDefSpec	0
W	0.8303	Cpu	2.4401	NWithinSpec	62
WpValue	0.0000	Cpk	2.4401	NOutsideSpec	0
90%	13.636E06	Skew	1.4980		
75%	12.500E06	Kurtosis	3.5804		
Median	11.010E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

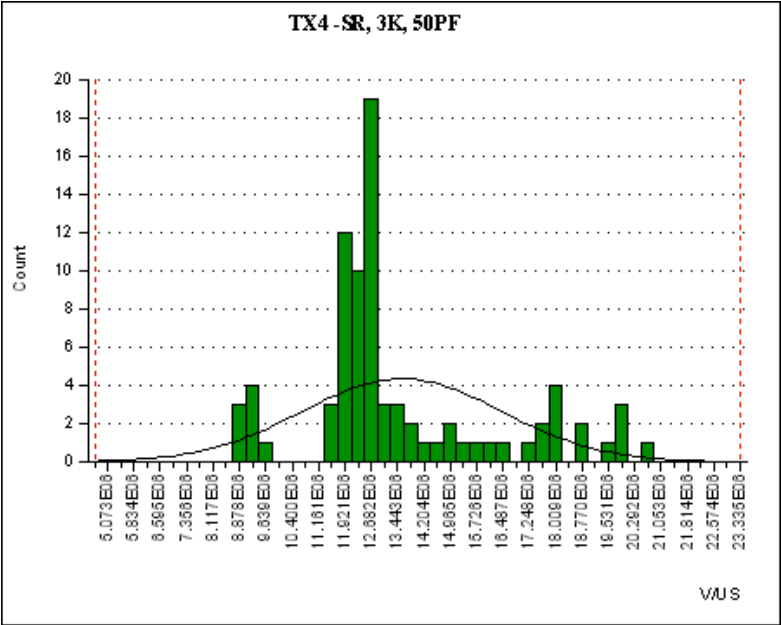
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
32.892E06	-5.964E06	100.00	0	62	0

Plot limits applied

NOutsidePlot

0

Test.Number=11.007, Test.Name=TX4 -SR, 3K, 50PF



Statistics: (V/US)

Max	20.690E06	25%	12.000E06	SpecHigh	23.335E06
Mean	13.483E06	10%	11.538E06	SpecLow	4.693E06
Min	8.824E06	N	82	PctWithinSpec	100.00
Range	11.866E06	Cp	1.0878	PctDefSpec	0
StdDev	2.856E06	Cpl	1.0259	NWithinSpec	82
W	0.8715	Cpu	1.1498	NOutsideSpec	0
WpValue	0.0000	Cpk	1.0259		
90%	18.182E06	Skew	0.8853		
75%	14.634E06	Kurtosis	0.2432		
Median	12.500E06				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

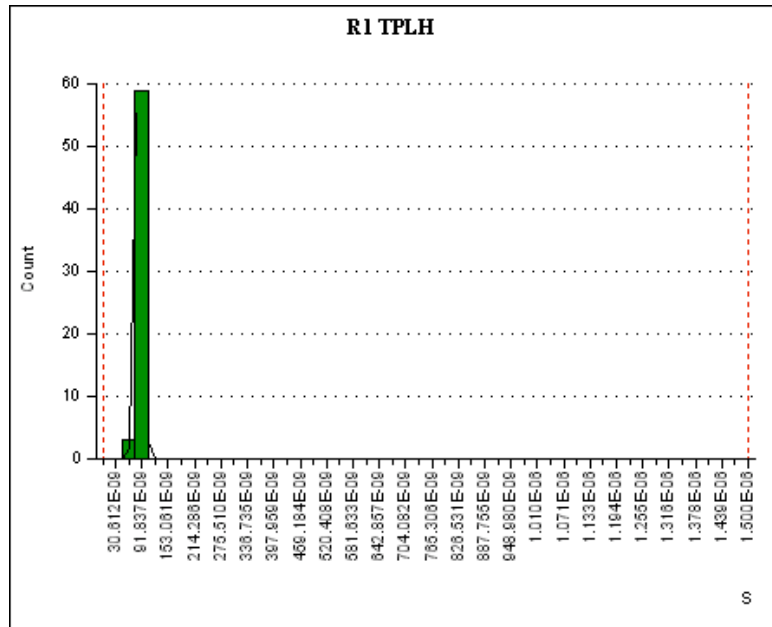
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=12.000, Test.Name=R1 TPLH



Statistics: (S)

Max	92.564E-09	25%	77.432E-09	SpecHigh	1.500E-06
Mean	83.323E-09	10%	76.874E-09	SpecLow	0
Min	56.873E-09	N	62	PctWithinSpec	100.00
Range	35.691E-09	Cp	>4.0000	PctDefSpec	0
StdDev	8.212E-09	Cpl	3.3821	NWithinSpec	62
W	0.7779	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	3.3821		
90%	91.634E-09	Skew	-0.8934		
75%	90.798E-09	Kurtosis	1.2128		
Median	79.338E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

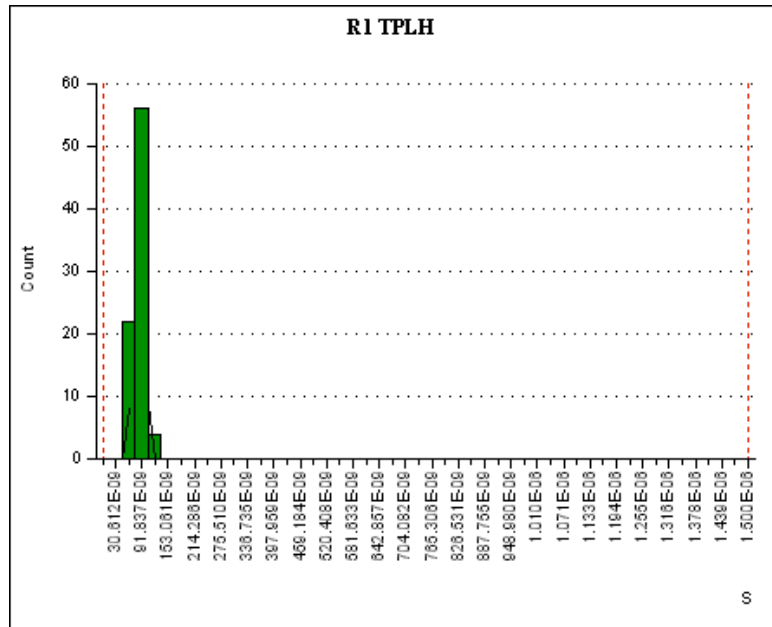
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.000, Test.Name=R1 TPLH



Statistics: (S)

Max	108.703E-09	25%	75.100E-09	SpecHigh	1.500E-06
Mean	82.706E-09	10%	68.493E-09	SpecLow	0
Min	67.832E-09	N	82	PctWithinSpec	100.00
Range	40.871E-09	Cp	>4.0000	PctDefSpec	0
StdDev	10.122E-09	Cpl	2.7236	NWithinSpec	82
W	0.8105	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	2.7236		
90%	85.672E-09	Skew	0.8444		
75%	84.728E-09	Kurtosis	1.2103		
Median	84.067E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

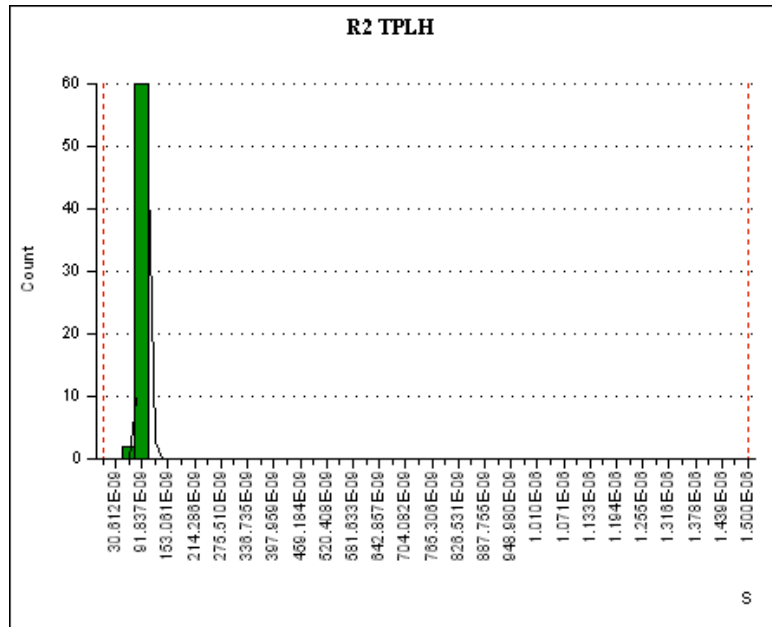
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.001, Test.Name=R2 TPLH



Statistics: (S)

Max	106.041E-09	25%	87.753E-09	SpecHigh	1.500E-06
Mean	94.862E-09	10%	86.730E-09	SpecLow	0
Min	63.472E-09	N	62	PctWithinSpec	100.00
Range	42.569E-09	Cp	>4.0000	PctDefSpec	0
StdDev	9.768E-09	Cpl	3.2371	NWithinSpec	62
W	0.7861	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	3.2371		
90%	104.461E-09	Skew	-0.7833		
75%	103.903E-09	Kurtosis	0.7468		
Median	89.752E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

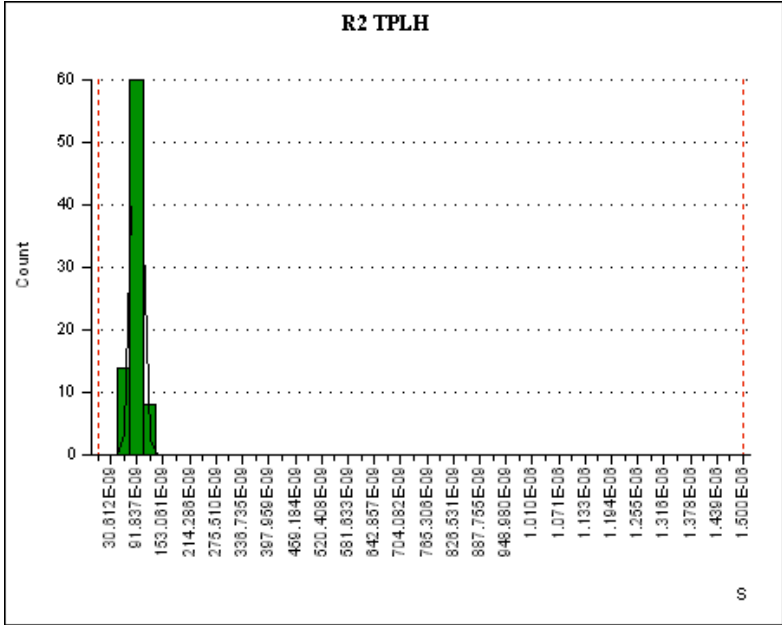
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.001, Test.Name=R2 TPLH



Statistics: (S)

Max	120.030E-09	25%	80.575E-09	SpecHigh	1.500E-06
Mean	89.359E-09	10%	73.779E-09	SpecLow	0
Min	71.797E-09	N	82	PctWithinSpec	100.00
Range	48.233E-09	Cp	>4.0000	c	
StdDev	11.429E-09	Cpl	2.6062	PctDefSpec	0
W	0.8135	Cpu	>4.0000	NWithinSpec	82
WpValue	0.0000	Cpk	2.6062	NOutsideSpec	0
90%	93.223E-09	Skew	0.8947		
75%	91.619E-09	Kurtosis	1.2880		
Median	91.052E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

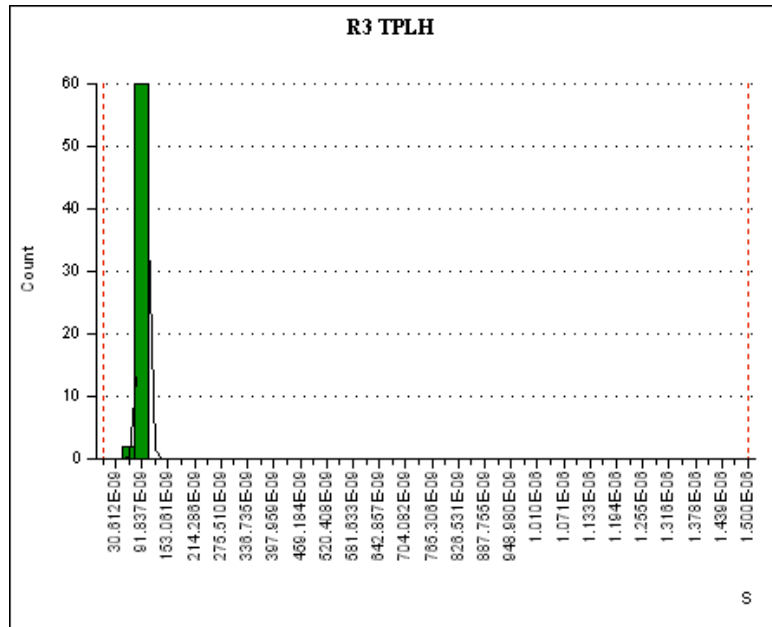
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=12.002, Test.Name=R3 TPLH



Statistics: (S)

Max	103.996E-09	25%	85.893E-09	SpecHigh	1.500E-06
Mean	93.061E-09	10%	85.428E-09	SpecLow	0
Min	62.914E-09	N	62	PctWithinSpec	100.00
Range	41.082E-09	Cp	>4.0000	PctDefSpec	0
StdDev	9.465E-09	Cpl	3.2774	NWithinSpec	62
W	0.7816	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	3.2774		
90%	102.695E-09	Skew	-0.7425		
75%	101.487E-09	Kurtosis	0.5878		
Median	88.171E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

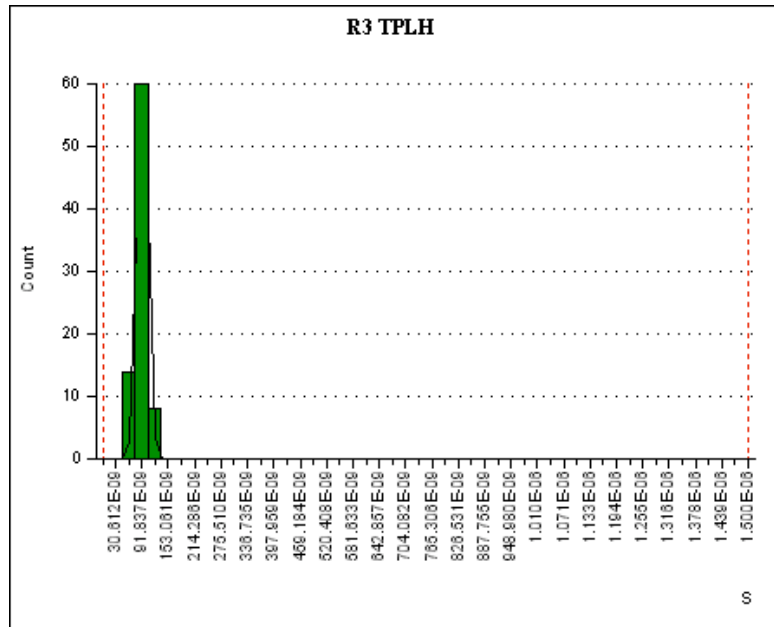
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.002, Test.Name=R3 TPLH



Statistics: (S)

Max	120.974E-09	25%	81.613E-09	SpecHigh	1.500E-06
Mean	90.475E-09	10%	75.006E-09	SpecLow	0
Min	73.684E-09	N	82	PctWithinSpec	100.00
Range	47.289E-09	Cp	>4.0000	PctDefSpec	0
StdDev	11.536E-09	Cpl	2.6144	NWithinSpec	82
W	0.8078	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	2.6144		
90%	93.789E-09	Skew	0.9640		
75%	92.940E-09	Kurtosis	1.3986		
Median	91.807E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

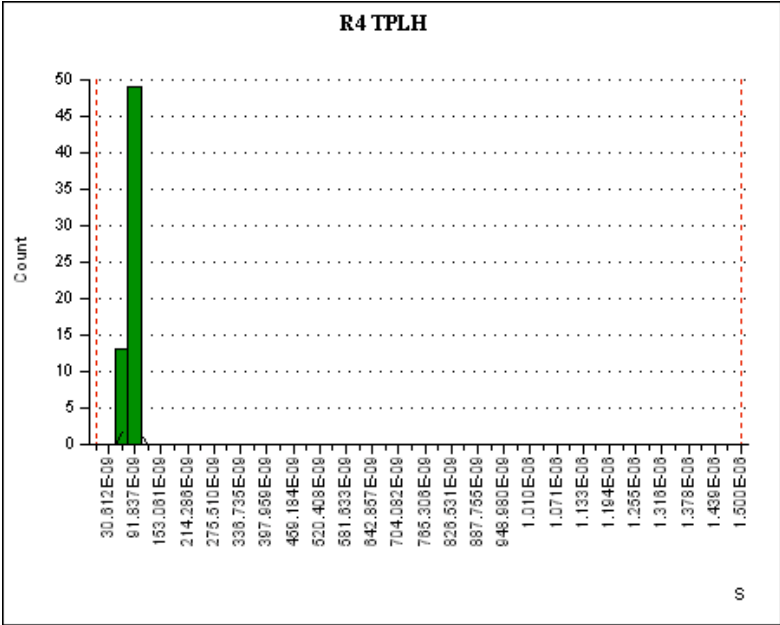
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.003, Test.Name=R4 TPLH



Statistics: (S)

Max	91.634E-09	25%	76.596E-09	SpecHigh	1.500E-06
Mean	82.124E-09	10%	76.038E-09	SpecLow	0
Min	56.408E-09	N	62	PctWithinSpec	100.00
Range	35.226E-09	Cp	>4.0000	c	
StdDev	7.741E-09	Cpl	3.5365	PctDefSpec	0
W	0.7833	Cpu	>4.0000	NWithinSpec	62
WpValue	0.0000	Cpk	3.5365	NOutsideSpec	0
90%	89.590E-09	Skew	-1.0103		
75%	88.939E-09	Kurtosis	1.7189		
Median	78.873E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01.AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01.AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01.AT	-	0

Data: Raw Data

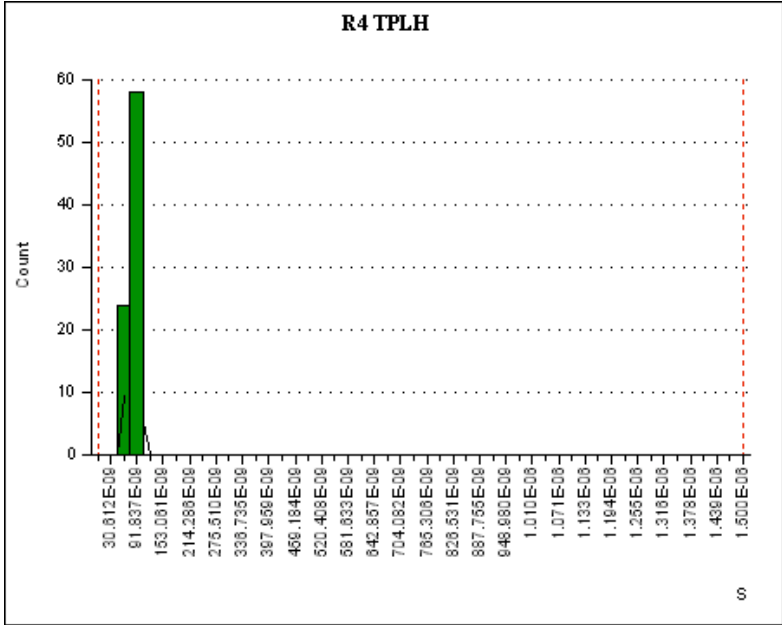
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=12.003, Test.Name=R4 TPLH



Statistics: (S)

Max	106.060E-09	25%	73.401E-09	SpecHigh	1.500E-06
Mean	81.298E-09	10%	67.927E-09	SpecLow	0
Min	66.228E-09	N	82	PctWithinSpec	100.00
Range	39.833E-09	Cp	>4.0000	PctDefSpec	0
StdDev	9.727E-09	Cpl	2.7859	NWithinSpec	82
W	0.8088	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	2.7859		
90%	84.539E-09	Skew	0.8463		
75%	83.312E-09	Kurtosis	1.2002		
Median	82.604E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

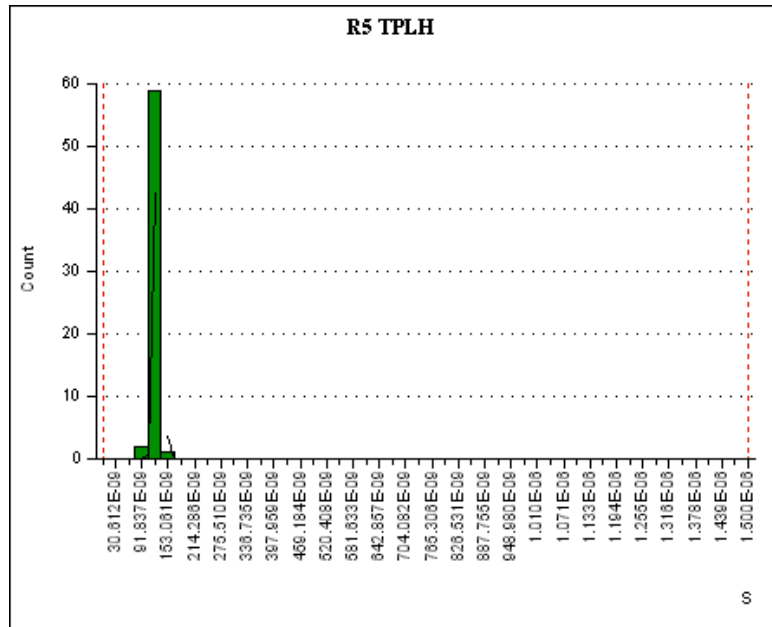
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=12.004, Test.Name=R5 TPLH



Statistics: (S)

Max	138.479E-09	25%	127.082E-09	SpecHigh	1.500E-06
Mean	130.026E-09	10%	126.431E-09	SpecLow	0
Min	91.541E-09	N	62	PctWithinSpec	100.00
Range	46.937E-09	Cp	>4.0000	PctDefSpec	0
StdDev	7.764E-09	Cpl	>4.0000	NWithinSpec	62
W	0.5928	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	135.133E-09	Skew	-3.6881		
75%	134.017E-09	Kurtosis	16.4785		
Median	132.595E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

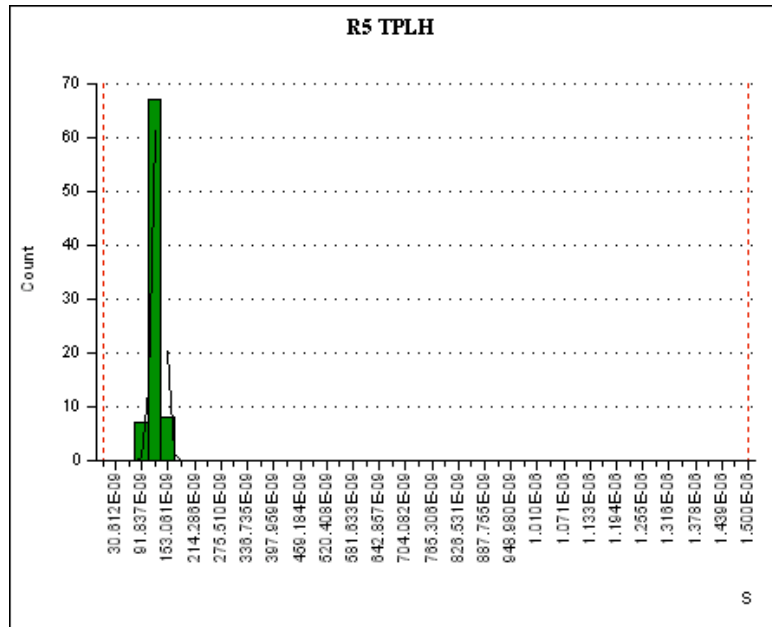
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.004, Test.Name=R5 TPLH



Statistics: (S)

Max	154.388E-09	25%	116.726E-09	SpecHigh	1.500E-06
Mean	129.055E-09	10%	107.382E-09	SpecLow	0
Min	105.588E-09	N	82	PctWithinSpec	100.00
Range	48.800E-09	Cp	>4.0000	c	
StdDev	12.702E-09	Cpl	3.3867	PctDefSpec	0
W	0.8518	Cpu	>4.0000	NWithinSpec	82
WpValue	0.0000	Cpk	3.3867	NOutsideSpec	0
90%	137.020E-09	Skew	-0.5143		
75%	135.227E-09	Kurtosis	-0.4775		
Median	133.953E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

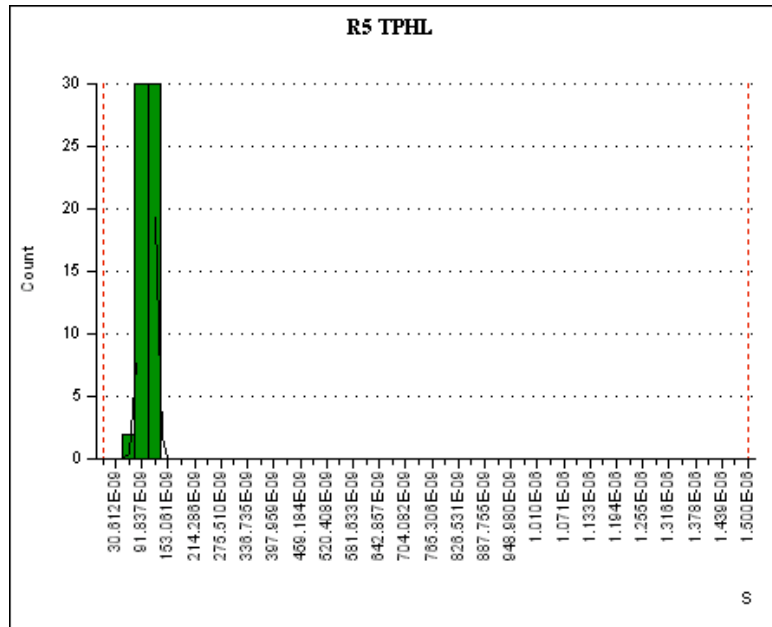
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.005, Test.Name=R5 TPHL



Statistics: (S)

Max	114.871E-09	25%	90.635E-09	SpecHigh	1.500E-06
Mean	100.849E-09	10%	90.263E-09	SpecLow	0
Min	66.353E-09	N	62	PctWithinSpec	100.00
Range	48.517E-09	Cp	>4.0000	PctDefSpec	0
StdDev	12.790E-09	Cpl	2.6284	NWithinSpec	62
W	0.7663	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	2.6284		
90%	114.313E-09	Skew	-0.4259		
75%	113.384E-09	Kurtosis	-0.6151		
Median	91.704E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

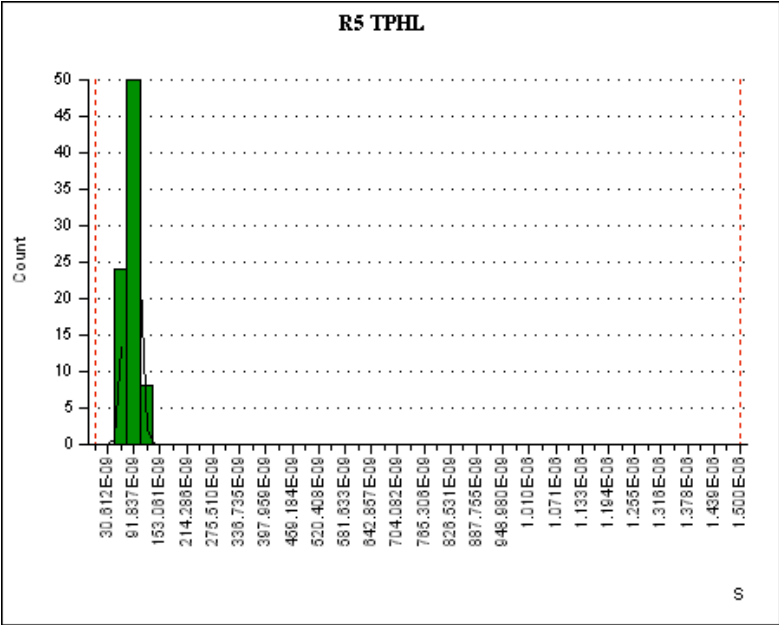
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.005, Test.Name=R5 TPHL



Statistics: (S)

Max	118.897E-09	25%	74.062E-09	SpecHigh	1.500E-06
Mean	84.476E-09	10%	66.699E-09	SpecLow	0
Min	65.284E-09	N	82	PctWithinSpec	100.00
Range	53.614E-09	Cp	>4.0000	c	
StdDev	13.110E-09	Cpl	2.1478	PctDefSpec	0
W	0.7974	Cpu	>4.0000	NWithinSpec	82
WpValue	0.0000	Cpk	2.1478	NOutsideSpec	0
90%	88.032E-09	Skew	0.9039		
75%	86.899E-09	Kurtosis	1.2652		
Median	86.380E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

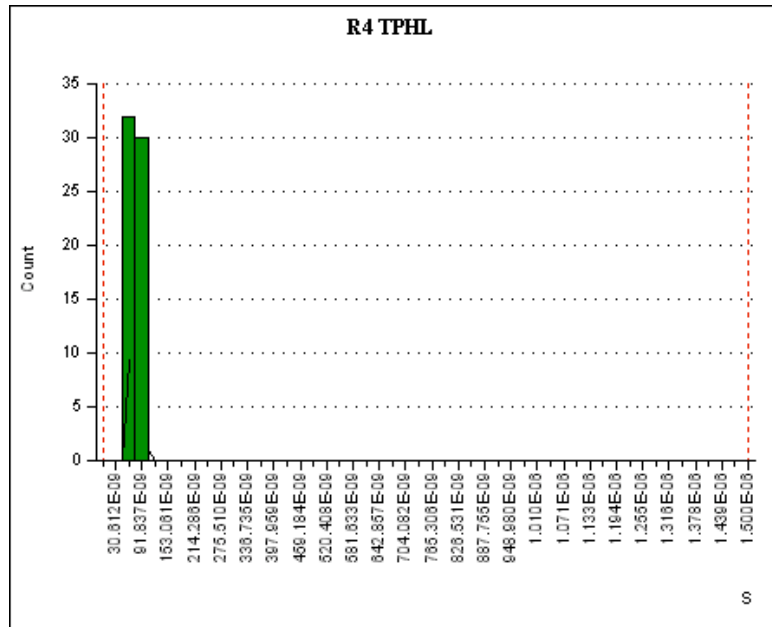
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=12.006, Test.Name=R4 TPHL



Statistics: (S)

Max	87.824E-09	25%	71.854E-09	SpecHigh	1.500E-06
Mean	78.543E-09	10%	71.389E-09	SpecLow	0
Min	52.226E-09	N	62	PctWithinSpec	100.00
Range	35.598E-09	Cp	>4.0000	PctDefSpec	0
StdDev	8.789E-09	Cpl	2.9788	NWithinSpec	62
W	0.7662	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	2.9788		
90%	87.452E-09	Skew	-0.6202		
75%	86.987E-09	Kurtosis	0.1008		
Median	72.830E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

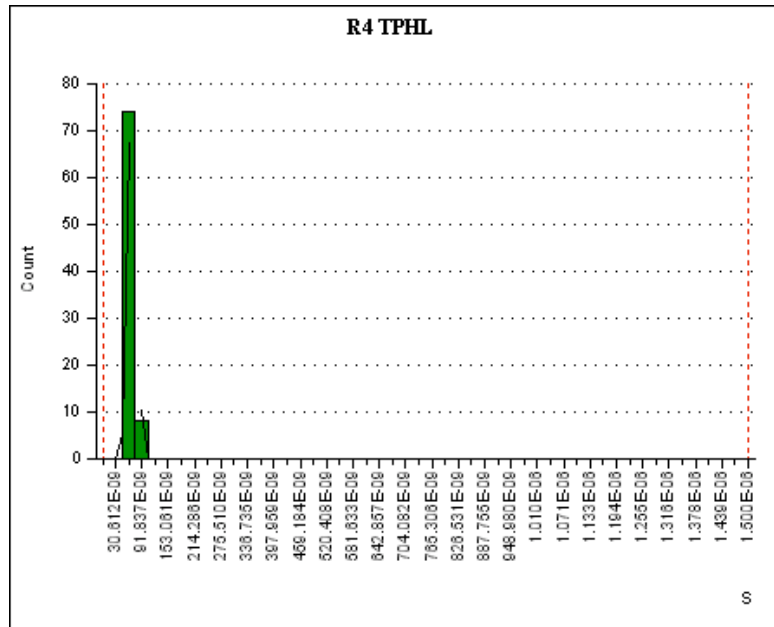
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.006, Test.Name=R4 TPHL



Statistics: (S)

Max	94.639E-09	25%	60.847E-09	SpecHigh	1.500E-06
Mean	68.945E-09	10%	55.561E-09	SpecLow	0
Min	54.429E-09	N	82	PctWithinSpec	100.00
Range	40.210E-09	Cp	>4.0000	c	
StdDev	9.847E-09	Cpl	2.3339	PctDefSpec	0
W	0.8030	Cpu	>4.0000	NWithinSpec	82
WpValue	0.0000	Cpk	2.3339	NOutsideSpec	0
90%	71.797E-09	Skew	0.8528		
75%	70.853E-09	Kurtosis	1.1414		
Median	70.286E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

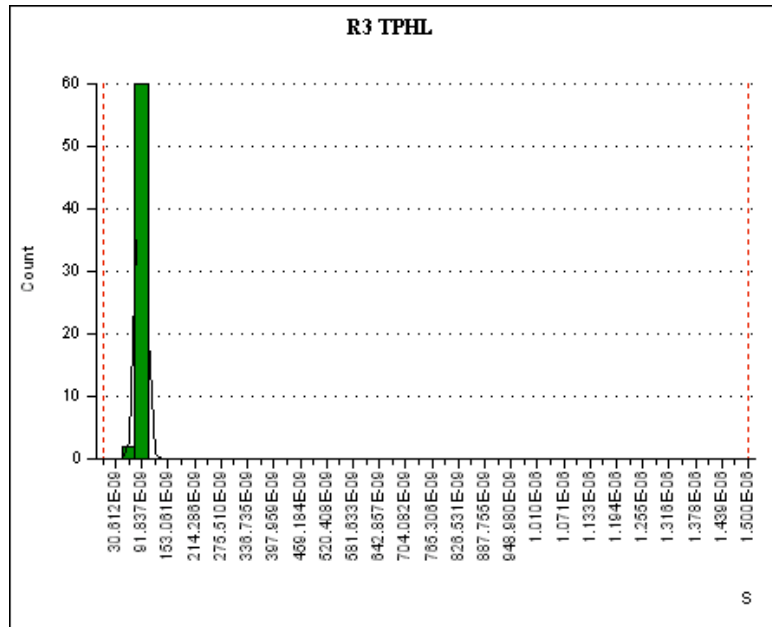
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.007, Test.Name=R3 TPHL



Statistics: (S)

Max	100.000E-09	25%	79.199E-09	SpecHigh	1.500E-06
Mean	87.725E-09	10%	78.827E-09	SpecLow	0
Min	57.524E-09	N	62	PctWithinSpec	100.00
Range	42.476E-09	Cp	>4.0000	PctDefSpec	0
StdDev	10.844E-09	Cpl	2.6966	NWithinSpec	62
W	0.7661	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	2.6966		
90%	98.791E-09	Skew	-0.4857		
75%	98.234E-09	Kurtosis	-0.4008		
Median	80.082E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

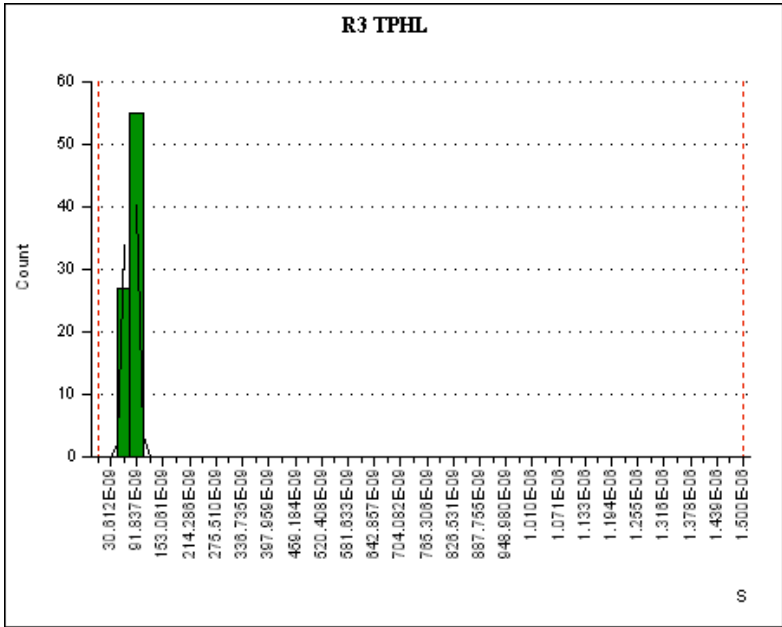
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.007, Test.Name=R3 TPHL



Statistics: (S)

Max	106.627E-09	25%	66.416E-09	SpecHigh	1.500E-06
Mean	75.744E-09	10%	60.564E-09	SpecLow	0
Min	59.054E-09	N	82	PctWithinSpec	100.00
Range	47.573E-09	Cp	>4.0000	c	
StdDev	11.404E-09	Cpl	2.2140	PctDefSpec	0
W	0.7958	Cpu	>4.0000	NWithinSpec	82
WpValue	0.0000	Cpk	2.2140	NOutsideSpec	0
90%	78.404E-09	Skew	0.9823		
75%	77.932E-09	Kurtosis	1.3990		
Median	77.177E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

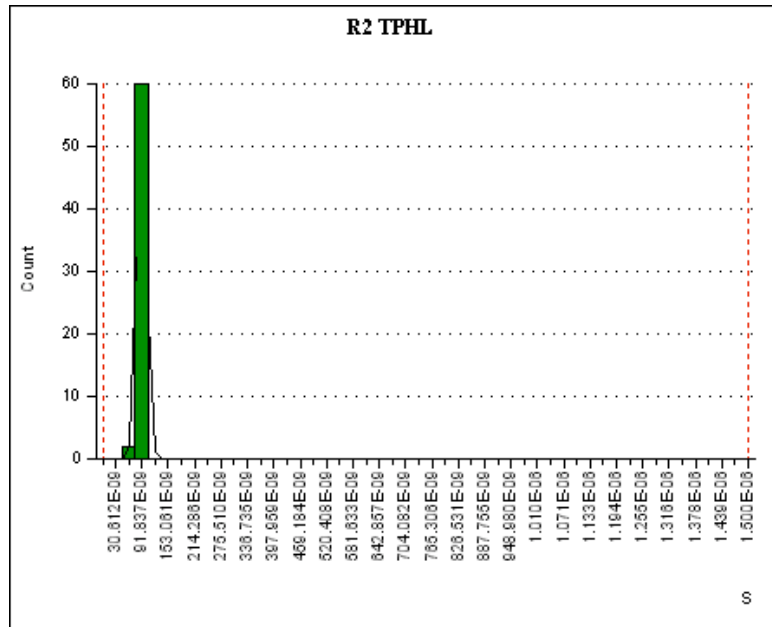
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=12.008, Test.Name=R2 TPHL



Statistics: (S)

Max	100.185E-09	25%	79.943E-09	SpecHigh	1.500E-06
Mean	88.491E-09	10%	79.478E-09	SpecLow	0
Min	57.895E-09	N	62	PctWithinSpec	100.00
Range	42.290E-09	Cp	>4.0000	PctDefSpec	0
StdDev	10.935E-09	Cpl	2.6974	NWithinSpec	62
W	0.7572	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	2.6974		
90%	99.628E-09	Skew	-0.4839		
75%	99.070E-09	Kurtosis	-0.4125		
Median	80.547E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

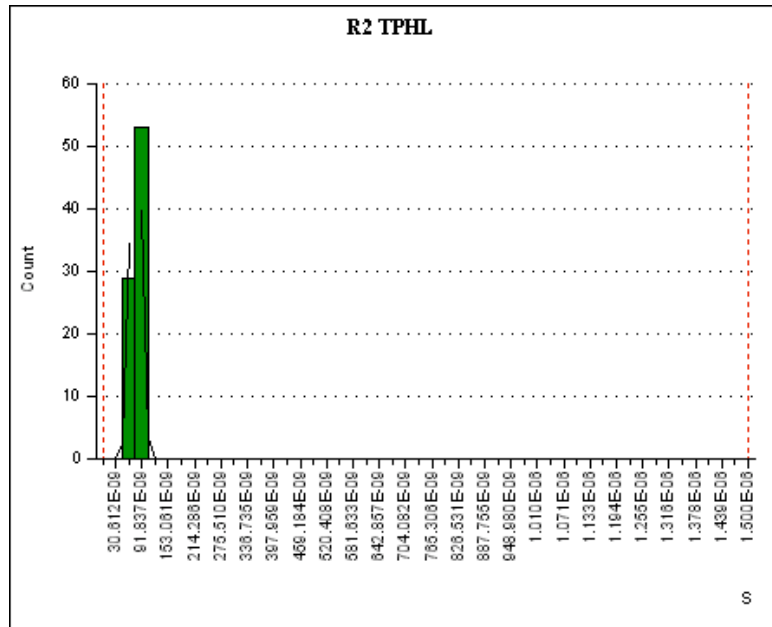
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.008, Test.Name=R2 TPHL



Statistics: (S)

Max	106.532E-09	25%	66.699E-09	SpecHigh	1.500E-06
Mean	75.604E-09	10%	60.375E-09	SpecLow	0
Min	58.865E-09	N	82	PctWithinSpec	100.00
Range	47.667E-09	Cp	>4.0000	PctDefSpec	0
StdDev	11.424E-09	Cpl	2.2059	NWithinSpec	82
W	0.7997	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	2.2059		
90%	78.876E-09	Skew	0.9736		
75%	77.743E-09	Kurtosis	1.3927		
Median	77.082E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

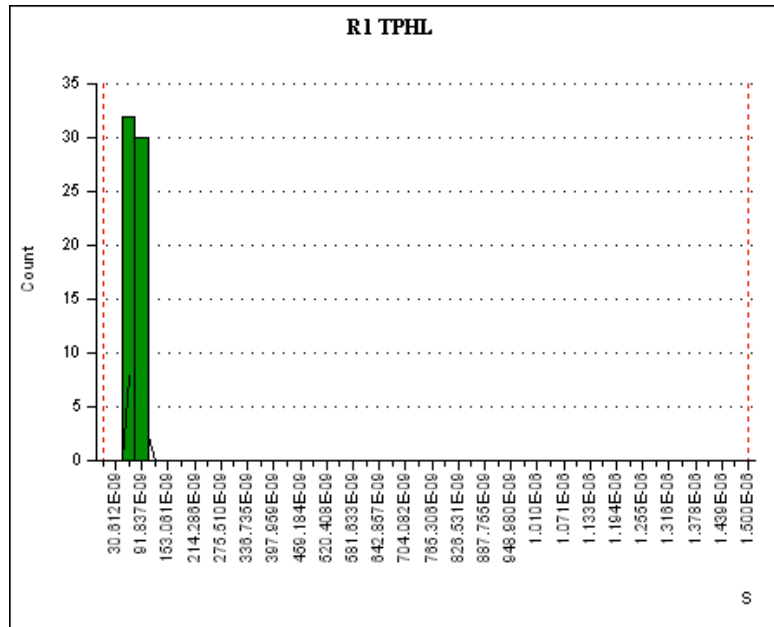
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.009, Test.Name=R1 TPHL



Statistics: (S)

Max	90.519E-09	25%	72.877E-09	SpecHigh	1.500E-06
Mean	80.104E-09	10%	72.505E-09	SpecLow	0
Min	53.527E-09	N	62	PctWithinSpec	100.00
Range	36.992E-09	Cp	>4.0000	c	
StdDev	9.293E-09	Cpl	2.8734	PctDefSpec	0
W	0.7645	Cpu	>4.0000	NWithinSpec	62
WpValue	0.0000	Cpk	2.8734	NOutsideSpec	0
90%	89.404E-09	Skew	-0.5611		
75%	89.032E-09	Kurtosis	-0.1337		
Median	73.853E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

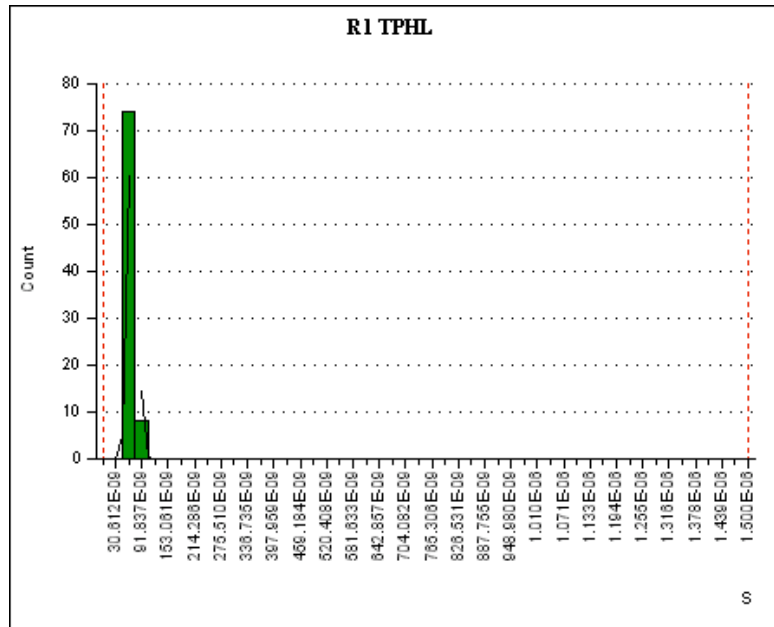
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=12.009, Test.Name=R1 TPHL



Statistics: (S)

Max	97.093E-09	25%	61.697E-09	SpecHigh	1.500E-06
Mean	70.048E-09	10%	56.317E-09	SpecLow	0
Min	54.995E-09	N	82	PctWithinSpec	100.00
Range	42.098E-09	Cp	>4.0000	PctDefSpec	0
StdDev	10.220E-09	Cpl	2.2846	NWithinSpec	82
W	0.7982	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	2.2846		
90%	72.929E-09	Skew	0.9194		
75%	71.985E-09	Kurtosis	1.2868		
Median	71.419E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

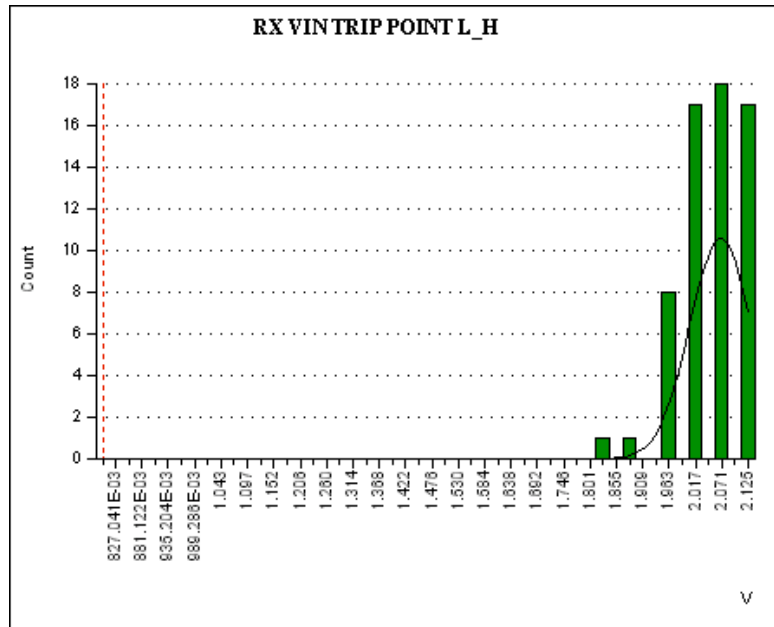
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.000, Test.Name=RX VIN TRIP POINT L_H



Statistics: (V)

Max	2.125	25%	2.025	SpecHigh	N/A
Mean	2.055	10%	1.975	SpecLow	800.000E-03
Min	1.825	N	62	PctWithinSpec	100.00
Range	299.999E-03	Cp	N/A	PctDefSpec	0
StdDev	63.025E-03	Cpl	>4.0000	NWithinSpec	62
W	0.8595	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	2.125	Skew	-1.1139		
75%	2.125	Kurtosis	2.1089		
Median	2.075				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

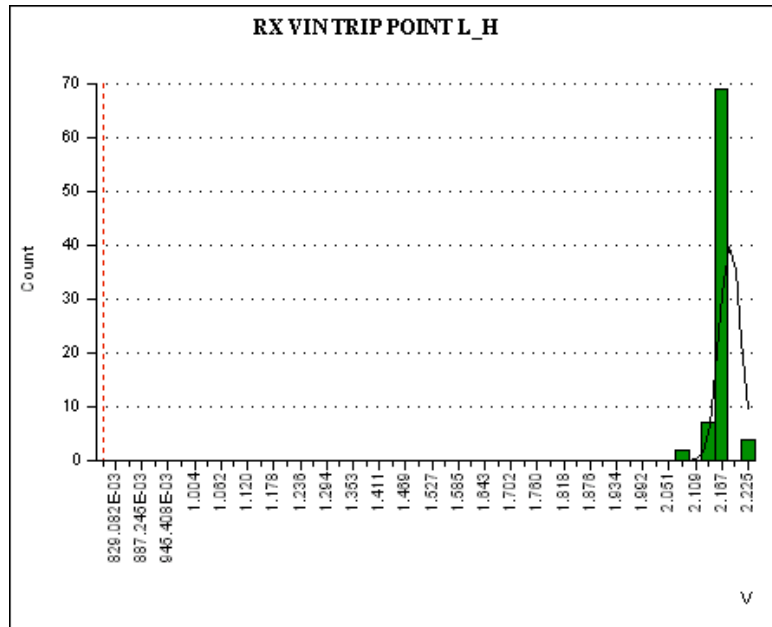
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.000, Test.Name=RX VIN TRIP POINT L_H



Statistics: (V)

Max	2.225	25%	2.175	SpecHigh	N/A
Mean	2.171	10%	2.125	SpecLow	800.000E-03
Min	2.075	N	82	PctWithinSpec	100.00
Range	150.000E-03	Cp	N/A	c	
StdDev	23.832E-03	Cpl	>4.0000	PctDefSpec	0
W	0.5374	Cpu	N/A	NWithinSpec	82
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	2.175	Skew	-1.6636		
75%	2.175	Kurtosis	6.5009		
Median	2.175				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T		0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T		0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T		0

Data: Raw Data

Stat limits applied

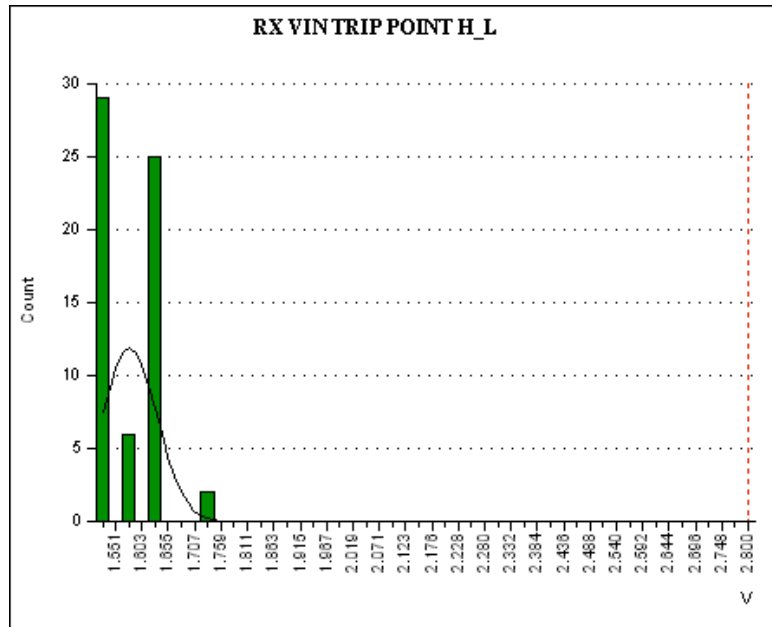
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.001, Test.Name=RX VIN TRIP POINT H_L



Statistics: (V)

Max	1.725	25%	1.525	SpecHigh	2.800
Mean	1.577	10%	1.525	SpecLow	N/A
Min	1.525	N	62	PctWithinSpec	100.00
Range	200.000E-03	Cp	N/A	PctDefSpec	0
StdDev	54.297E-03	Cpl	N/A	NWithinSpec	62
W	0.7577	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	1.625	Skew	0.5693		
75%	1.625	Kurtosis	-0.4220		
Median	1.575				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

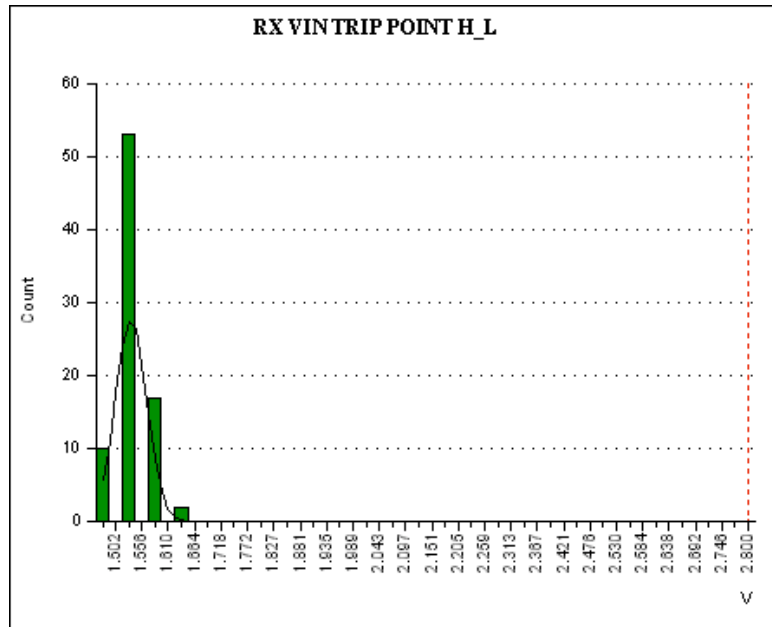
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.001, Test.Name=RX VIN TRIP POINT H_L



Statistics: (V)

Max	1.625	25%	1.525	SpecHigh	2.800
Mean	1.532	10%	1.475	SpecLow	N/A
Min	1.475	N	82	PctWithinSpec	100.00
Range	150.001E-03	Cp	N/A	PctDefSpec	0
StdDev	32.167E-03	Cpl	N/A	NWithinSpec	82
W	0.7814	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	1.575	Skew	0.4425		
75%	1.525	Kurtosis	0.7941		
Median	1.525				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

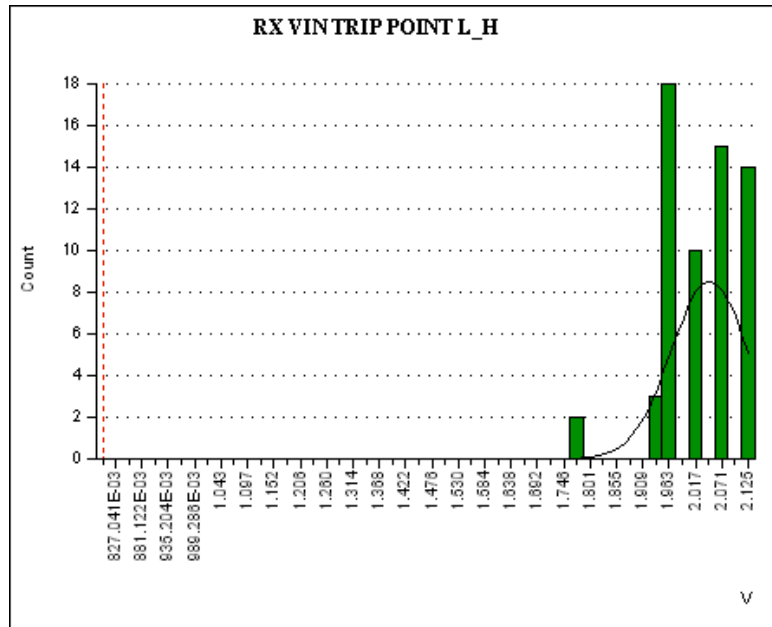
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.003, Test.Name=RX VIN TRIP POINT L_H



Statistics: (V)

Max	2.125	25%	1.975	SpecHigh	N/A
Mean	2.032	10%	1.975	SpecLow	800.000E-03
Min	1.775	N	62	PctWithinSpec	100.00
Range	349.999E-03	Cp	N/A	c	
StdDev	78.326E-03	Cpl	>4.0000	PctDefSpec	0
W	0.8653	Cpu	N/A	NWithinSpec	62
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	2.125	Skew	-1.0152		
75%	2.075	Kurtosis	1.8622		
Median	2.025				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

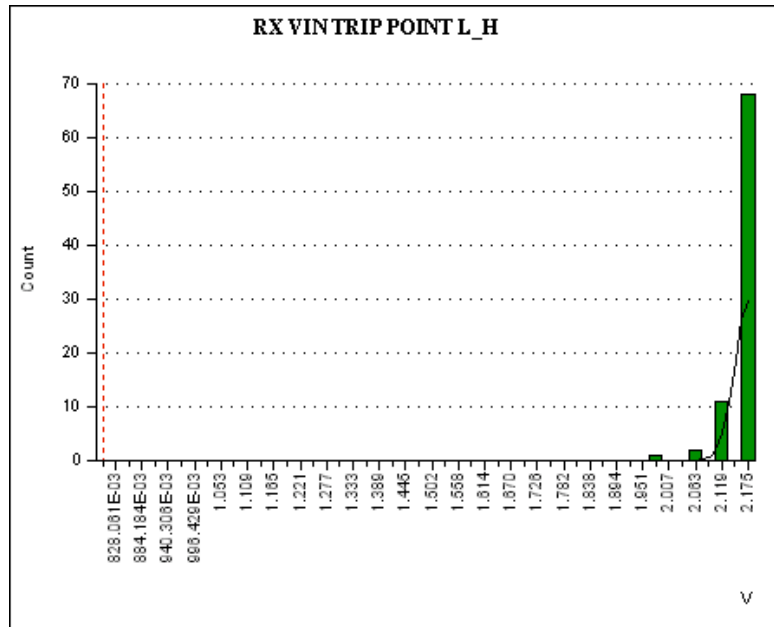
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N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.003, Test.Name=RX VIN TRIP POINT L_H



Statistics: (V)

Max	2.175	25%	2.175	SpecHigh	N/A
Mean	2.163	10%	2.125	SpecLow	800.000E-03
Min	1.975	N	82	PctWithinSpec	100.00
Range	200.000E-03	Cp	N/A	c	
StdDev	30.731E-03	Cpl	>4.0000	PctDefSpec	0
W	0.4272	Cpu	N/A	NWithinSpec	82
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	2.175	Skew	-3.7451		
75%	2.175	Kurtosis	17.8702		
Median	2.175				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

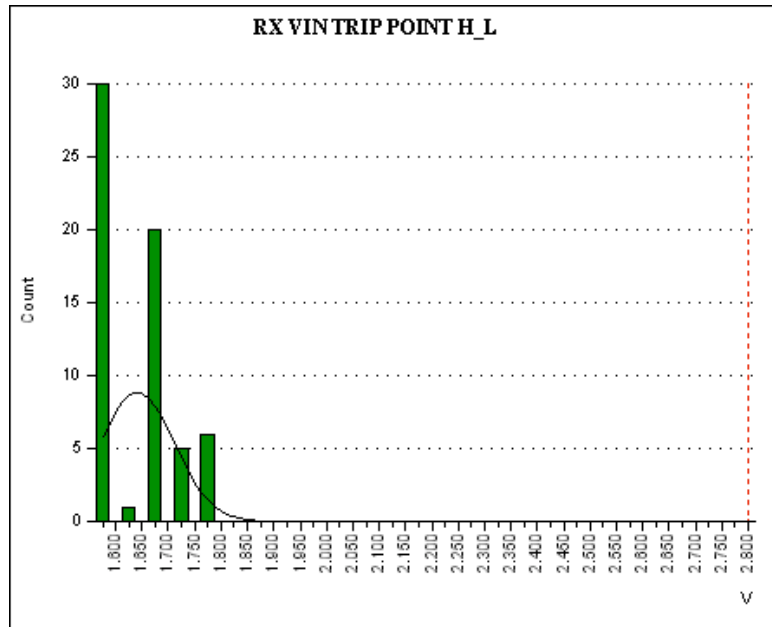
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.004, Test.Name=RX VIN TRIP POINT H_L



Statistics: (V)

Max	1.775	25%	1.575	SpecHigh	2.800
Mean	1.640	10%	1.575	SpecLow	N/A
Min	1.575	N	62	PctWithinSpec	100.00
Range	200.000E-03	Cp	N/A	c	
StdDev	69.769E-03	Cpl	N/A	PctDefSpec	0
W	0.7887	Cpu	>4.0000	NWithinSpec	62
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	1.725	Skew	0.5426		
75%	1.675	Kurtosis	-0.9853		
Median	1.650				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

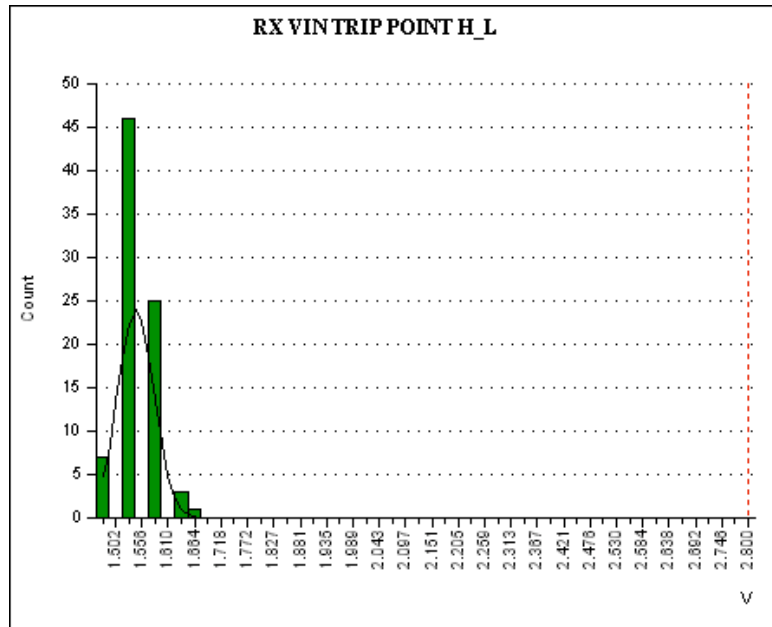
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.004, Test.Name=RX VIN TRIP POINT H_L



Statistics: (V)

Max	1.675	25%	1.525	SpecHigh	2.800
Mean	1.541	10%	1.525	SpecLow	N/A
Min	1.475	N	82	PctWithinSpec	100.00
Range	200.000E-03	Cp	N/A	PctDefSpec	0
StdDev	36.897E-03	Cpl	N/A	NWithinSpec	82
W	0.8145	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	1.575	Skew	0.7085		
75%	1.575	Kurtosis	1.4453		
Median	1.525				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

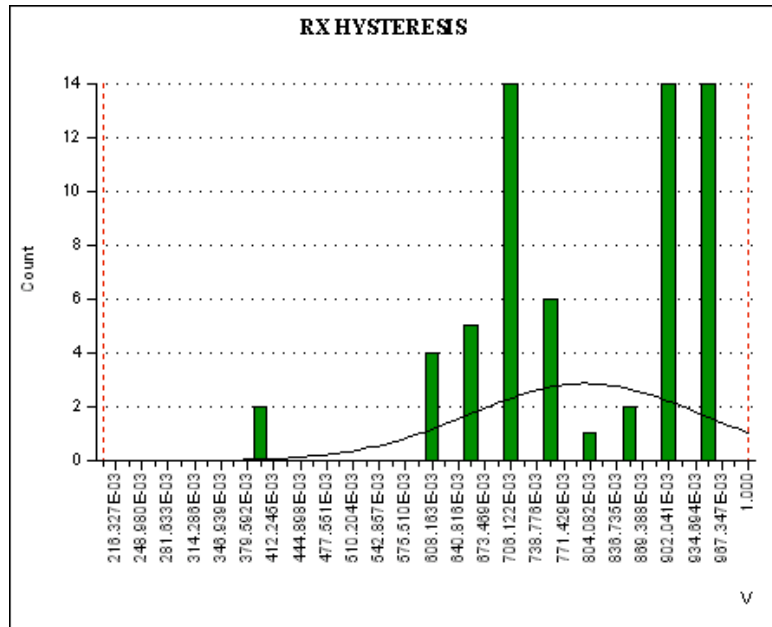
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.005, Test.Name=RX HYSTERESIS



Statistics: (V)

Max	950.000E-03	25%	700.001E-03	SpecHigh	1.000
Mean	792.743E-03	10%	650.001E-03	SpecLow	200.000E-03
Min	400.001E-03	N	62	PctWithinSpec	100.00
Range	549.999E-03	Cp	0.9490	c	
StdDev	140.504E-03	Cpl	1.4062	PctDefSpec	0
W	0.8738	Cpu	0.4917	NWithinSpec	62
WpValue	0.0000	Cpk	0.4917	NOutsideSpec	0
90%	950.000E-03	Skew	-0.6344		
75%	900.001E-03	Kurtosis	-0.0589		
Median	775.001E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

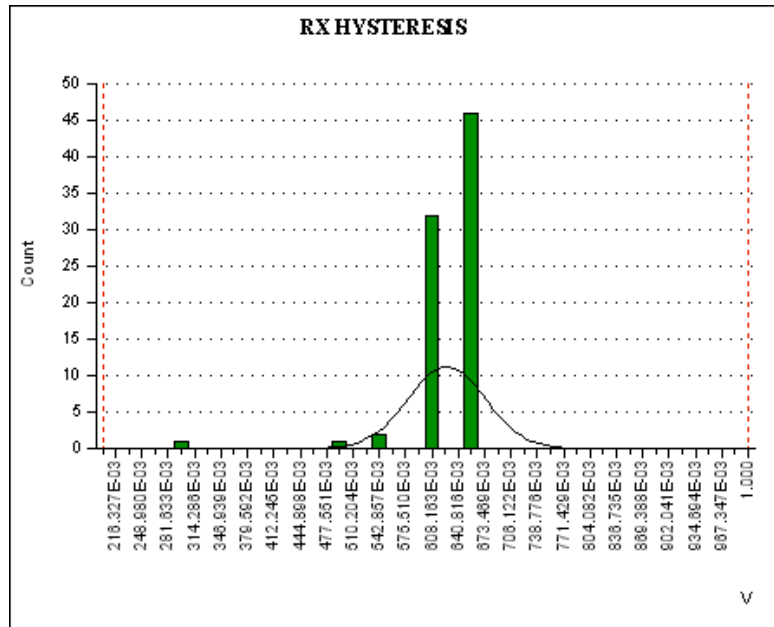
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.005, Test.Name=RX HYSTERESIS



Statistics: (V)

Max	650.001E-03	25%	600.000E-03	SpecHigh	1.000
Mean	621.952E-03	10%	600.000E-03	SpecLow	200.000E-03
Min	300.001E-03	N	82	PctWithinSpec	100.00
Range	349.999E-03	Cp	2.8246	c	
StdDev	47.204E-03	Cpl	2.9796	PctDefSpec	0
W	0.5304	Cpu	2.6696	NWithinSpec	82
WpValue	0.0000	Cpk	2.6696	NOutsideSpec	0
90%	650.001E-03	Skew	-4.2412		
75%	650.001E-03	Kurtosis	26.4863		
Median	650.001E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

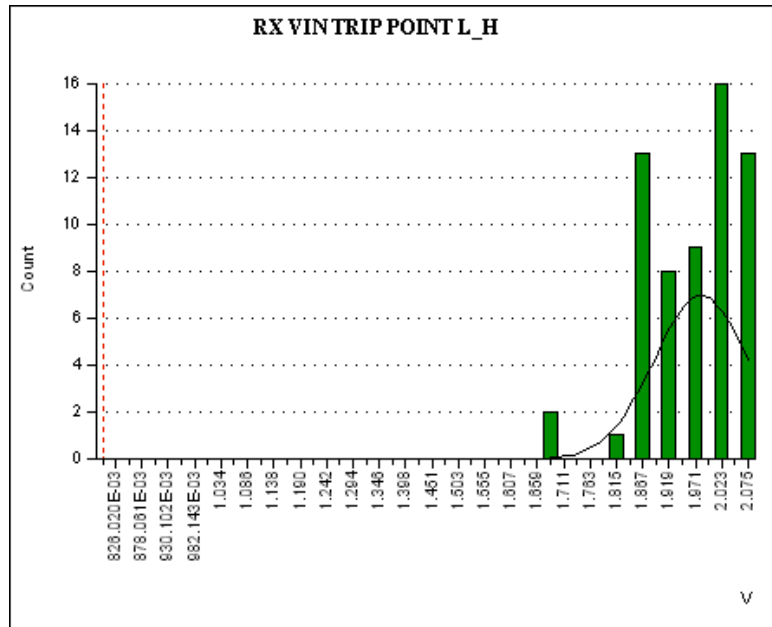
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.006, Test.Name=RX VIN TRIP POINT L_H



Statistics: (V)

Max	2.075	25%	1.875	SpecHigh	N/A
Mean	1.969	10%	1.875	SpecLow	800.000E-03
Min	1.675	N	62	PctWithinSpec	100.00
Range	400.001E-03	Cp	N/A	PctDefSpec	0
StdDev	92.375E-03	Cpl	>4.0000	NWithinSpec	62
W	0.8729	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	2.075	Skew	-1.0218		
75%	2.025	Kurtosis	1.3883		
Median	1.975				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

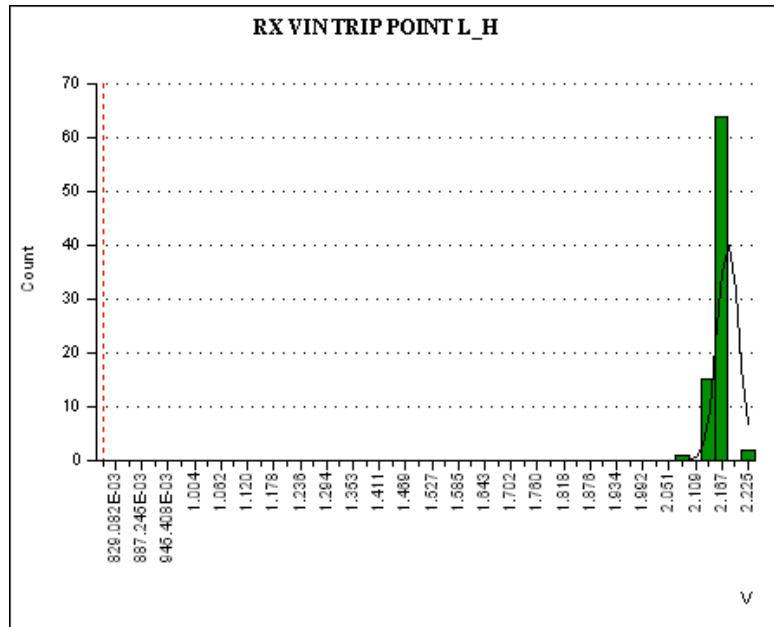
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.006, Test.Name=RX VIN TRIP POINT L_H



Statistics: (V)

Max	2.225	25%	2.175	SpecHigh	N/A
Mean	2.166	10%	2.125	SpecLow	800.000E-03
Min	2.075	N	82	PctWithinSpec	100.00
Range	150.000E-03	Cp	N/A	c	
StdDev	23.737E-03	Cpl	>4.0000	PctDefSpec	0
W	0.6023	Cpu	N/A	NWithinSpec	82
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	2.175	Skew	-1.2393		
75%	2.175	Kurtosis	2.5322		
Median	2.175				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

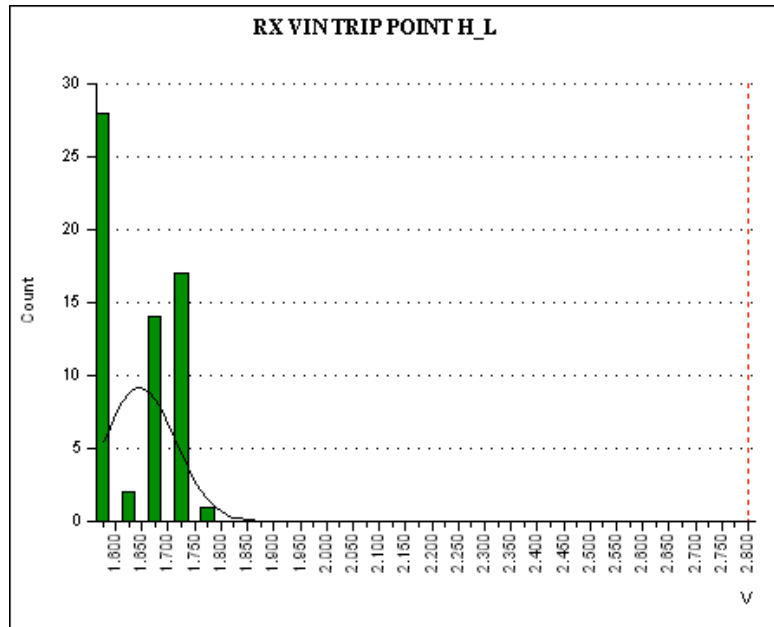
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.007, Test.Name=RX VIN TRIP POINT H_L



Statistics: (V)

Max	1.775	25%	1.575	SpecHigh	2.800
Mean	1.644	10%	1.575	SpecLow	N/A
Min	1.575	N	62	PctWithinSpec	100.00
Range	200.000E-03	Cp	N/A	c	
StdDev	67.286E-03	Cpl	N/A	PctDefSpec	0
W	0.7793	Cpu	>4.0000	NWithinSpec	62
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	1.725	Skew	0.1591		
75%	1.725	Kurtosis	-1.6717		
Median	1.675				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

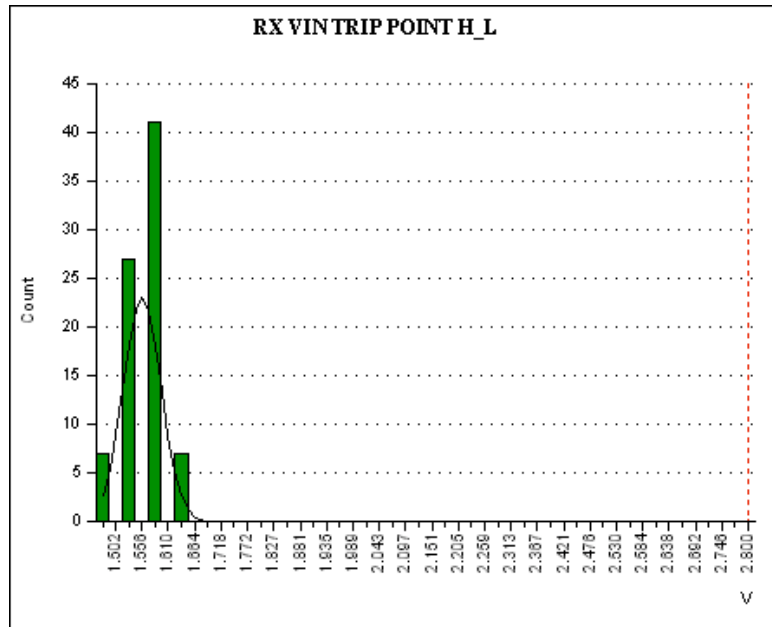
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.007, Test.Name=RX VIN TRIP POINT H_L



Statistics: (V)

Max	1.625	25%	1.525	SpecHigh	2.800
Mean	1.554	10%	1.525	SpecLow	N/A
Min	1.475	N	82	PctWithinSpec	100.00
Range	150.001E-03	Cp	N/A	c	
StdDev	38.451E-03	Cpl	N/A	PctDefSpec	0
W	0.8442	Cpu	>4.0000	NWithinSpec	82
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	1.575	Skew	-0.2941		
75%	1.575	Kurtosis	-0.2012		
Median	1.575				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

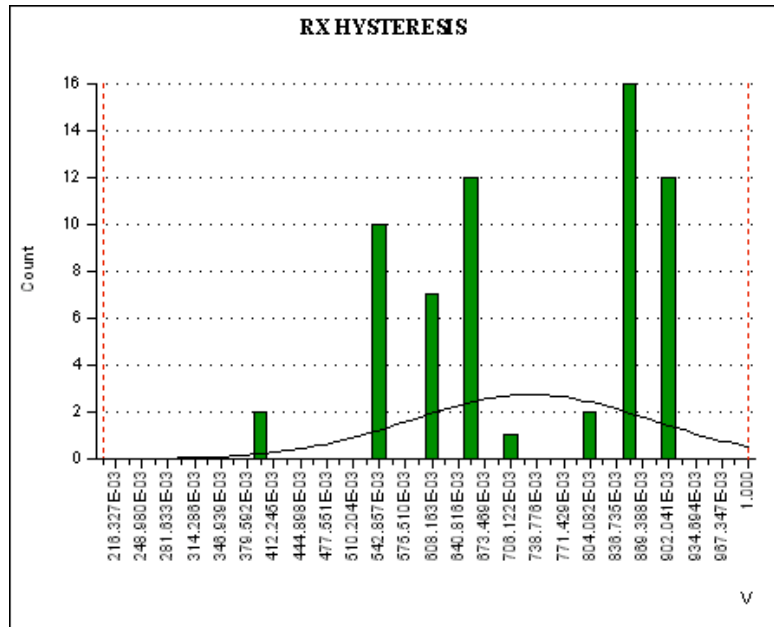
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.008, Test.Name=RX HYSTERESIS



Statistics: (V)

Max	900.001E-03	25%	600.001E-03	SpecHigh	1.000
Mean	725.807E-03	10%	550.001E-03	SpecLow	200.000E-03
Min	400.001E-03	N	62	PctWithinSpec	100.00
Range	500.000E-03	Cp	0.9051	PctDefSpec	0
StdDev	147.310E-03	Cpl	1.1898	NWithinSpec	62
W	0.8610	Cpu	0.6204	NOutsideSpec	0
WpValue	0.0000	Cpk	0.6204		
90%	900.001E-03	Skew	-0.2533		
75%	850.001E-03	Kurtosis	-1.2652		
Median	675.001E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

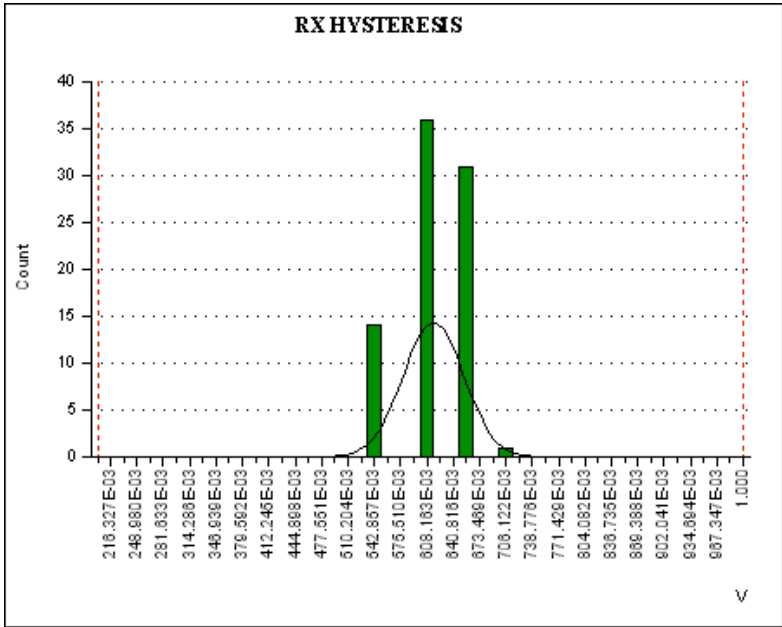
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.008, Test.Name=RX HYSTERESIS



Statistics: (V)

Max	700.001E-03	25%	600.000E-03	SpecHigh	1.000
Mean	611.586E-03	10%	550.000E-03	SpecLow	200.000E-03
Min	550.000E-03	N	82	PctWithinSpec	100.00
Range	150.001E-03	Cp	3.5938	PctDefSpec	0
StdDev	37.101E-03	Cpl	3.6979	NWithinSpec	82
W	0.8250	Cpu	3.4897	NOutsideSpec	0
WpValue	0.0000	Cpk	3.4897		
90%	650.001E-03	Skew	-0.2175		
75%	650.001E-03	Kurtosis	-0.7942		
Median	600.000E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

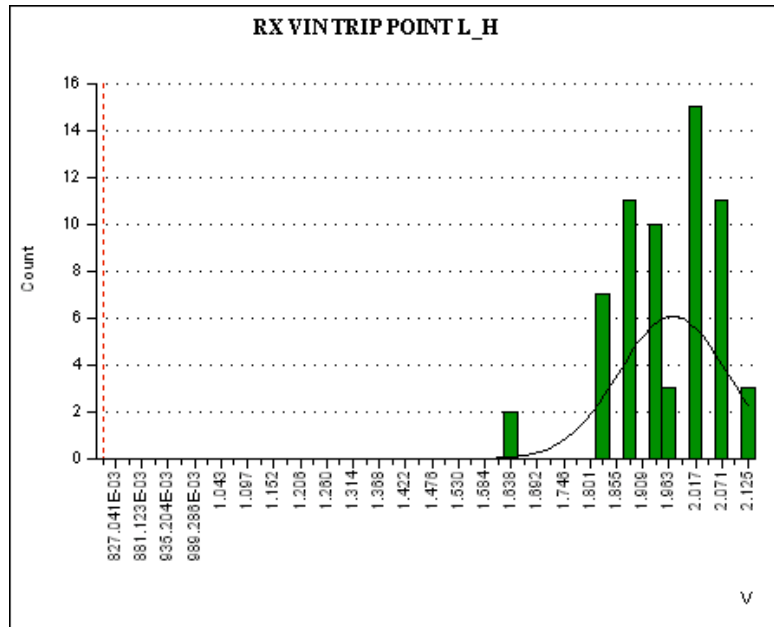
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=13.009, Test.Name=RX VIN TRIP POINT L_H



Statistics: (V)

Max	2.125	25%	1.875	SpecHigh	N/A
Mean	1.958	10%	1.825	SpecLow	800.000E-03
Min	1.625	N	62	PctWithinSpec	100.00
Range	500.000E-03	Cp	N/A	c	
StdDev	109.748E-03	Cpl	3.5174	PctDefSpec	0
W	0.9105	Cpu	N/A	NWithinSpec	62
WpValue	0.0003	Cpk	3.5174	NOutsideSpec	0
90%	2.075	Skew	-0.7817		
75%	2.025	Kurtosis	0.8403		
Median	1.975				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

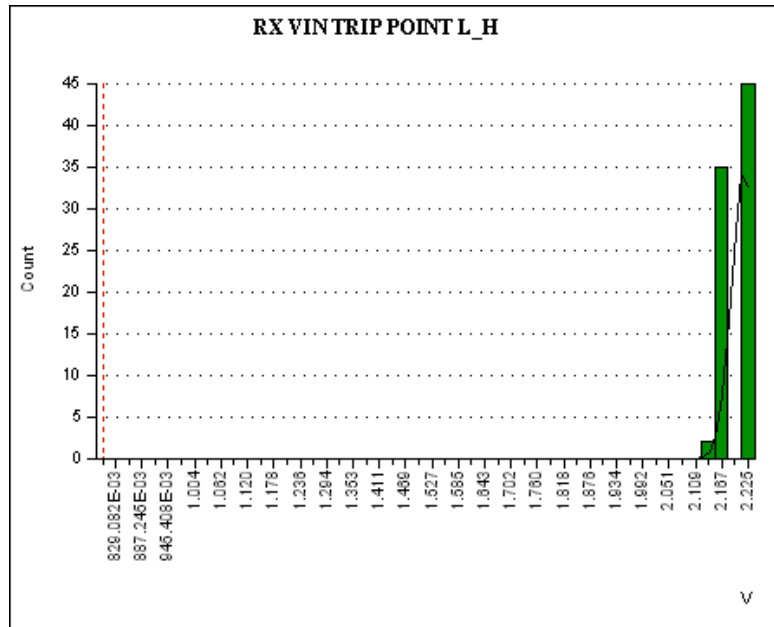
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N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.009, Test.Name=RX VIN TRIP POINT L_H



Statistics: (V)

Max	2.225	25%	2.175	SpecHigh	N/A
Mean	2.201	10%	2.175	SpecLow	800.000E-03
Min	2.125	N	82	PctWithinSpec	100.00
Range	99.999E-03	Cp	N/A	PctDefSpec	0
StdDev	27.471E-03	Cpl	>4.0000	NWithinSpec	82
W	0.6908	Cpu	N/A	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	2.225	Skew	-0.5562		
75%	2.225	Kurtosis	-0.8167		
Median	2.225				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

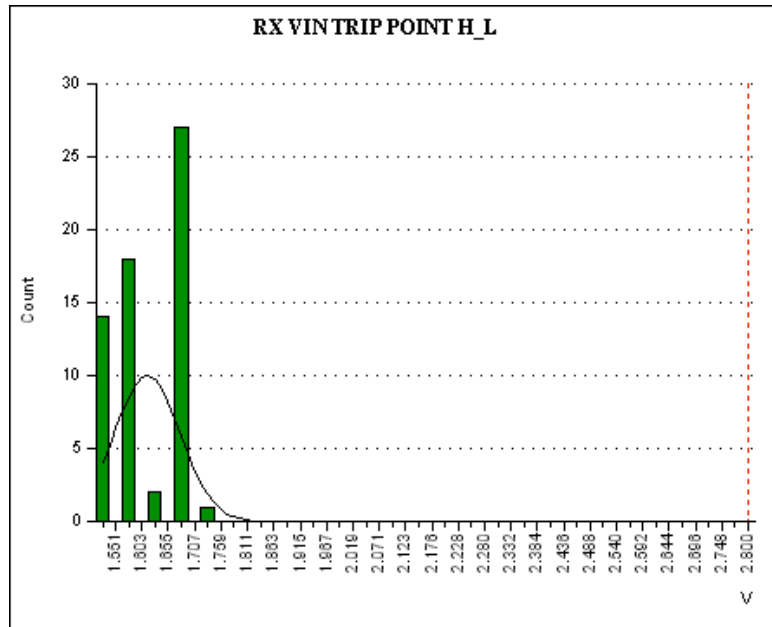
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.010, Test.Name=RX VIN TRIP POINT H_L



Statistics: (V)

Max	1.725	25%	1.575	SpecHigh	2.800
Mean	1.611	10%	1.525	SpecLow	N/A
Min	1.525	N	62	PctWithinSpec	100.00
Range	200.000E-03	Cp	N/A	PctDefSpec	0
StdDev	64.127E-03	Cpl	N/A	NWithinSpec	62
W	0.7980	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	1.675	Skew	-0.0898		
75%	1.675	Kurtosis	-1.6350		
Median	1.575				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

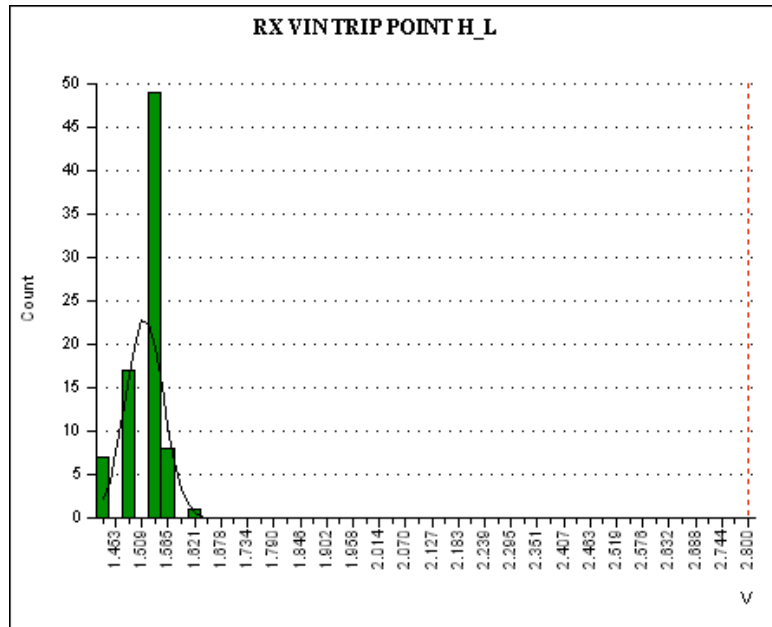
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.010, Test.Name=RX VIN TRIP POINT H_L



Statistics: (V)

Max	1.625	25%	1.475	SpecHigh	2.800
Mean	1.512	10%	1.475	SpecLow	N/A
Min	1.425	N	82	PctWithinSpec	100.00
Range	200.000E-03	Cp	N/A	PctDefSpec	0
StdDev	39.916E-03	Cpl	N/A	NWithinSpec	82
W	0.8240	Cpu	>4.0000	NOutsideSpec	0
WpValue	0.0000	Cpk	>4.0000		
90%	1.575	Skew	-0.3970		
75%	1.525	Kurtosis	0.6821		
Median	1.525				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

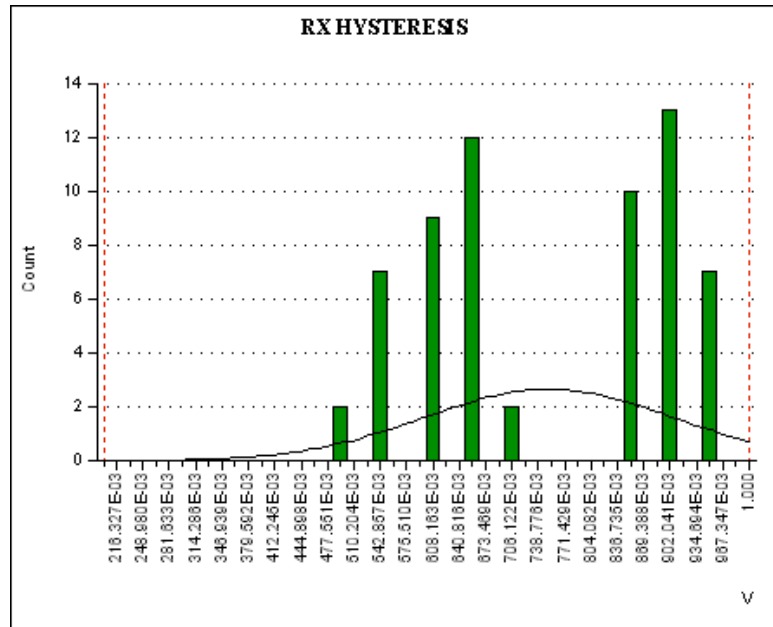
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.011, Test.Name=RX HYSTERESIS



Statistics: (V)

Max	950.001E-03	25%	600.002E-03	SpecHigh	1.000
Mean	746.775E-03	10%	550.002E-03	SpecLow	200.000E-03
Min	500.001E-03	N	62	PctWithinSpec	100.00
Range	450.000E-03	Cp	0.8788	PctDefSpec	0
StdDev	151.730E-03	Cpl	1.2012	NWithinSpec	62
W	0.8584	Cpu	0.5563	NOutsideSpec	0
WpValue	0.0000	Cpk	0.5563		
90%	950.001E-03	Skew	-0.0311		
75%	900.001E-03	Kurtosis	-1.6725		
Median	700.001E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

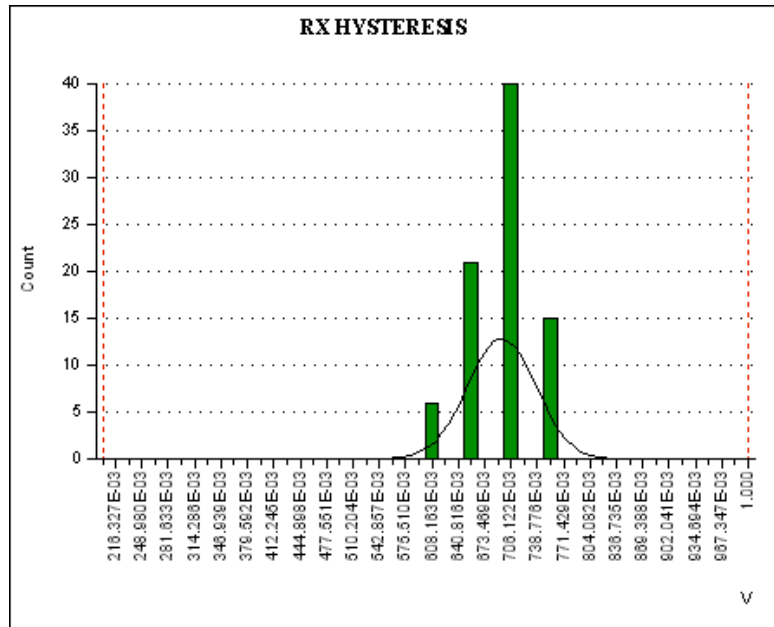
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.011, Test.Name=RX HYSTERESIS



Statistics: (V)

Max	750.001E-03	25%	650.001E-03	SpecHigh	1.000
Mean	689.025E-03	10%	650.001E-03	SpecLow	200.000E-03
Min	600.000E-03	N	82	PctWithinSpec	100.00
Range	150.001E-03	Cp	3.2057	PctDefSpec	0
StdDev	41.592E-03	Cpl	3.9192	NWithinSpec	82
W	0.8583	Cpu	2.4923	NOutsideSpec	0
WpValue	0.0000	Cpk	2.4923		
90%	750.001E-03	Skew	-0.3566		
75%	700.001E-03	Kurtosis	-0.2999		
Median	700.001E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

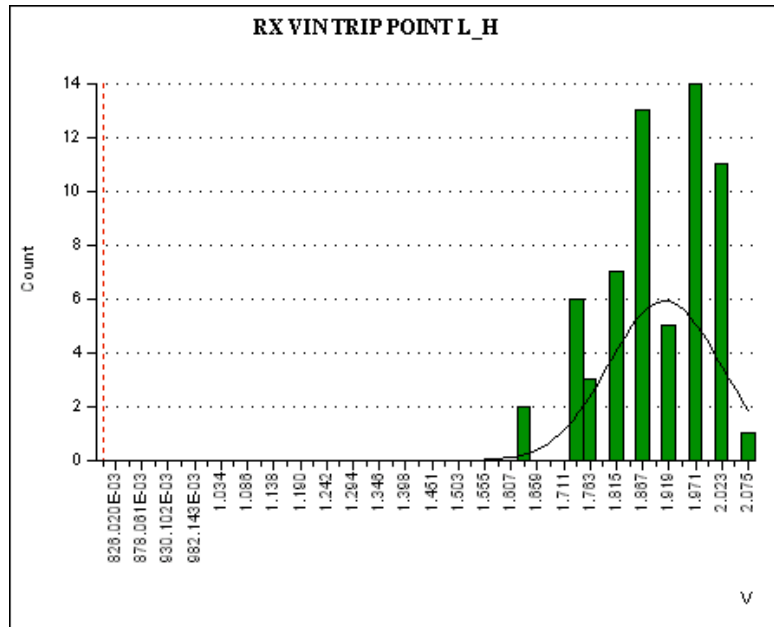
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.012, Test.Name=RX VIN TRIP POINT L_H



Statistics: (V)

Max	2.075	25%	1.825	SpecHigh	N/A
Mean	1.898	10%	1.725	SpecLow	800.000E-03
Min	1.625	N	62	PctWithinSpec	100.00
Range	450.000E-03	Cp	N/A	c	
StdDev	108.158E-03	Cpl	3.3851	PctDefSpec	0
W	0.9262	Cpu	N/A	NWithinSpec	62
WpValue	0.0011	Cpk	3.3851	NOutsideSpec	0
90%	2.025	Skew	-0.6224		
75%	1.975	Kurtosis	-0.2743		
Median	1.900				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

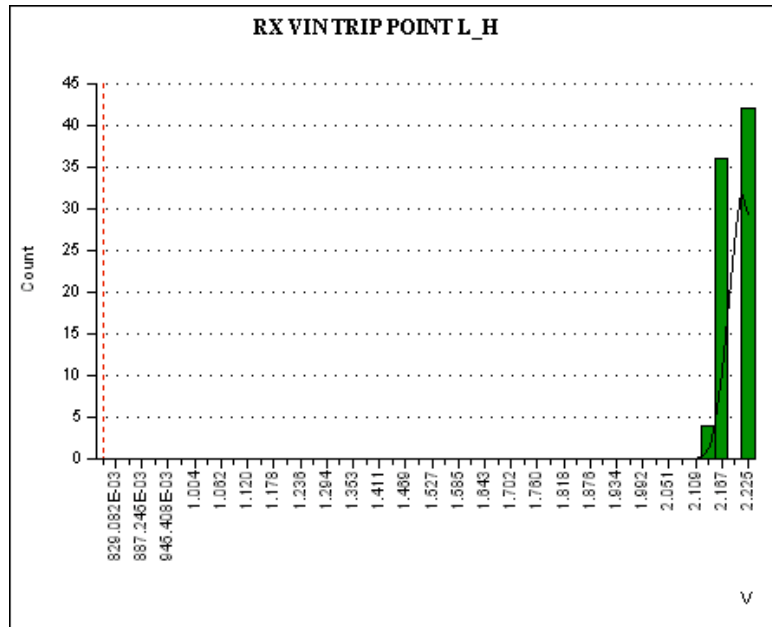
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.012, Test.Name=RX VIN TRIP POINT L_H



Statistics: (V)

Max	2.225	25%	2.175	SpecHigh	N/A
Mean	2.198	10%	2.175	SpecLow	800.000E-03
Min	2.125	N	82	PctWithinSpec	100.00
Range	99.999E-03	Cp	N/A	c	
StdDev	29.601E-03	Cpl	>4.0000	PctDefSpec	0
W	0.7227	Cpu	N/A	NWithinSpec	82
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	2.225	Skew	-0.5873		
75%	2.225	Kurtosis	-0.5725		
Median	2.225				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T		0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T		0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T		0

Data: Raw Data

Stat limits applied

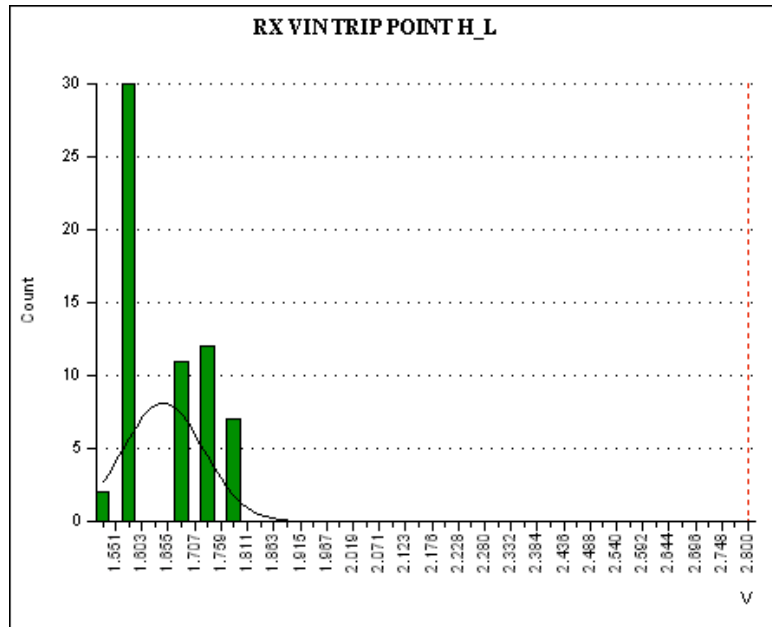
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.013, Test.Name=RX VIN TRIP POINT H_L



Statistics: (V)

Max	1.775	25%	1.575	SpecHigh	2.800
Mean	1.643	10%	1.575	SpecLow	N/A
Min	1.525	N	62	PctWithinSpec	100.00
Range	250.000E-03	Cp	N/A	c	
StdDev	78.977E-03	Cpl	N/A	PctDefSpec	0
W	0.8135	Cpu	>4.0000	NWithinSpec	62
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	1.775	Skew	0.3663		
75%	1.725	Kurtosis	-1.4242		
Median	1.575				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

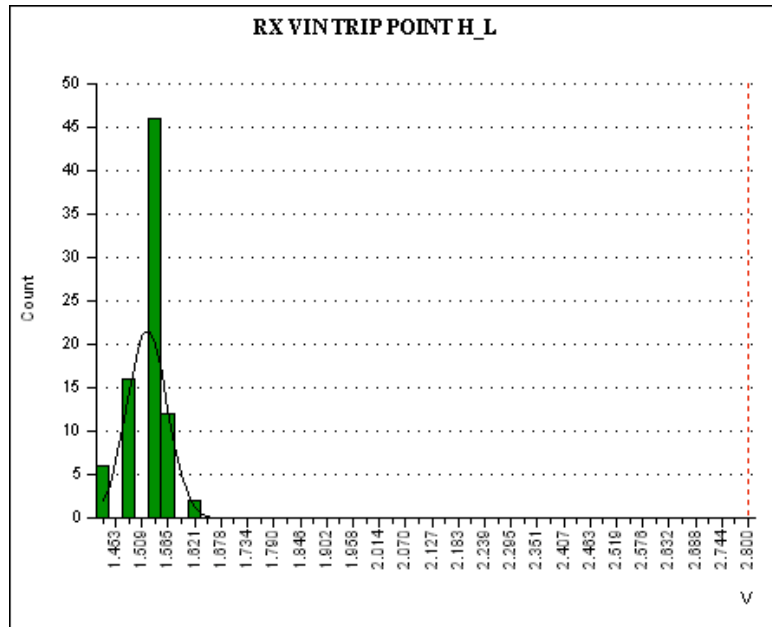
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.013, Test.Name=RX VIN TRIP POINT H_L



Statistics: (V)

Max	1.625	25%	1.475	SpecHigh	2.800
Mean	1.518	10%	1.475	SpecLow	N/A
Min	1.425	N	82	PctWithinSpec	100.00
Range	200.000E-03	Cp	N/A	c	
StdDev	42.399E-03	Cpl	N/A	PctDefSpec	0
W	0.8574	Cpu	>4.0000	NWithinSpec	82
WpValue	0.0000	Cpk	>4.0000	NOutsideSpec	0
90%	1.575	Skew	-0.2111		
75%	1.525	Kurtosis	0.5503		
Median	1.525				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

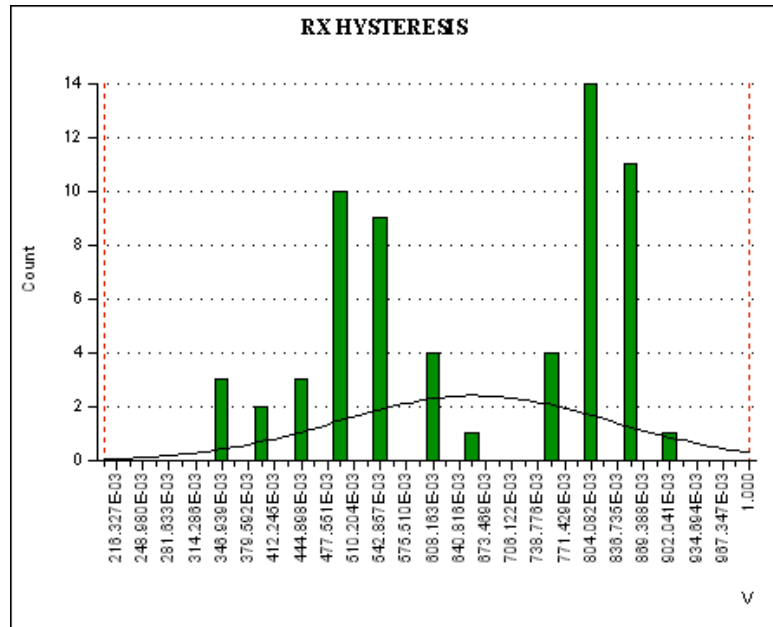
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.014, Test.Name=RX HYSTERESIS



Statistics: (V)

Max	900.001E-03	25%	500.001E-03	SpecHigh	1.000
Mean	655.646E-03	10%	450.001E-03	SpecLow	200.000E-03
Min	350.001E-03	N	62	PctWithinSpec	100.00
Range	550.000E-03	Cp	0.7997	PctDefSpec	0
StdDev	166.720E-03	Cpl	0.9110	NWithinSpec	62
W	0.8788	Cpu	0.6885	NOutsideSpec	0
WpValue	0.0000	Cpk	0.6885		
90%	850.001E-03	Skew	-0.1950		
75%	800.001E-03	Kurtosis	-1.4495		
Median	625.001E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

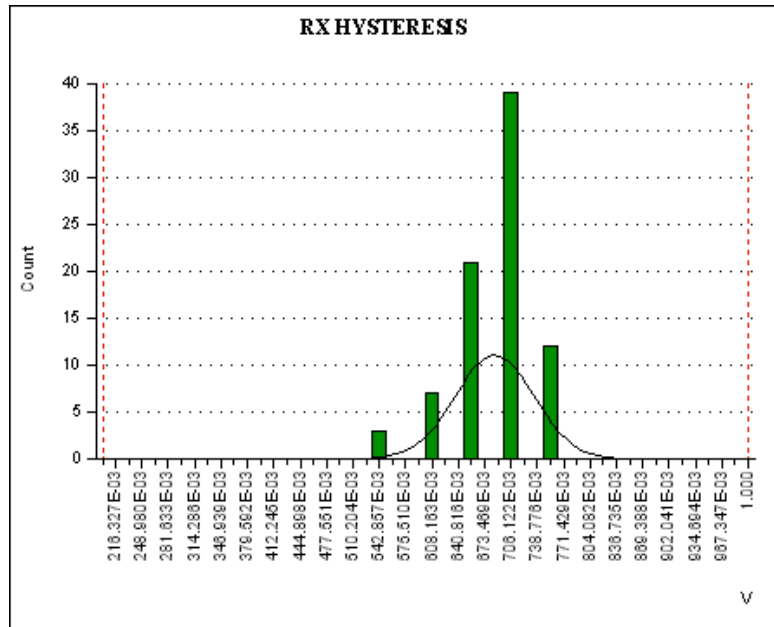
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=13.014, Test.Name=RX HYSTERESIS



Statistics: (V)

Max	750.001E-03	25%	650.001E-03	SpecHigh	1.000
Mean	680.489E-03	10%	600.000E-03	SpecLow	200.000E-03
Min	550.001E-03	N	82	PctWithinSpec	100.00
Range	200.000E-03	Cp	2.7619	PctDefSpec	0
StdDev	48.277E-03	Cpl	3.3176	NWithinSpec	82
W	0.8650	Cpu	2.2061	NOutsideSpec	0
WpValue	0.0000	Cpk	2.2061		
90%	750.001E-03	Skew	-0.7412		
75%	700.001E-03	Kurtosis	0.4775		
Median	700.001E-03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

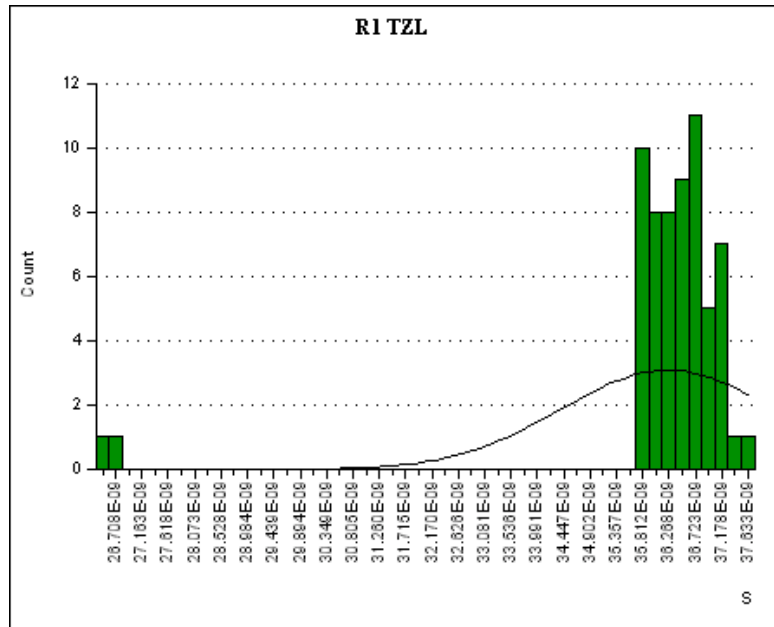
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

0

Test.Number=14.000, Test.Name=R1 TZL



Statistics: (S)

Max	37.633E-09	25%	36.058E-09	SpecHigh	N/A
Mean	36.153E-09	10%	35.779E-09	SpecLow	N/A
Min	26.480E-09	N	62	PctWithinSpec	N/A
Range	11.153E-09	Cp	N/A	c	
StdDev	1.824E-09	Cpl	N/A	PctDefSpec	N/A
W	0.3984	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	37.076E-09	Skew	-4.8628		
75%	36.797E-09	Kurtosis	24.4191		
Median	36.430E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01.AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01.AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01.AT	-	0

Data: Raw Data

Stat limits applied

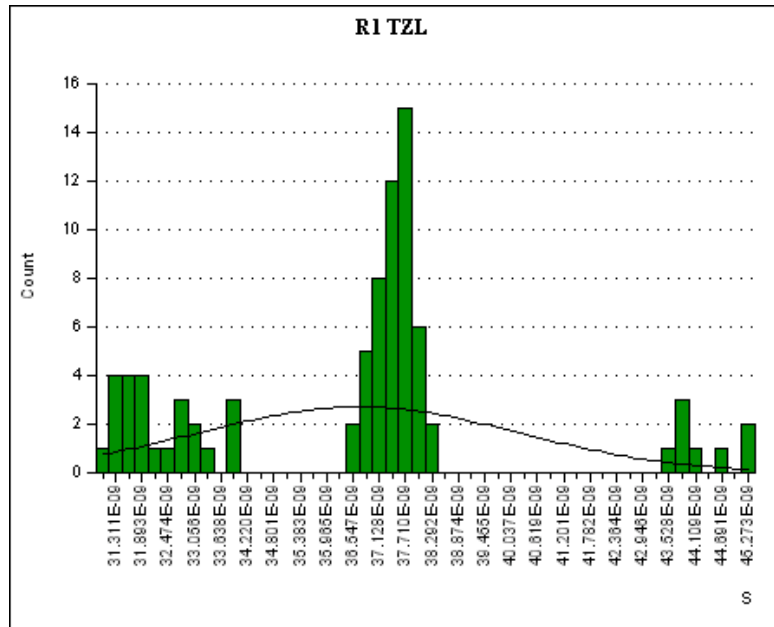
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.000, Test.Name=R1 TZL



Statistics: (S)

Max	45.273E-09	25%	33.380E-09	SpecHigh	N/A
Mean	36.622E-09	10%	31.586E-09	SpecLow	N/A
Min	31.020E-09	N	82	PctWithinSpec	N/A
Range	14.253E-09	Cp	N/A	PctDefSpec	N/A
StdDev	3.511E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8576	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	38.194E-09	Skew	0.4445		
75%	37.816E-09	Kurtosis	0.3771		
Median	37.344E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

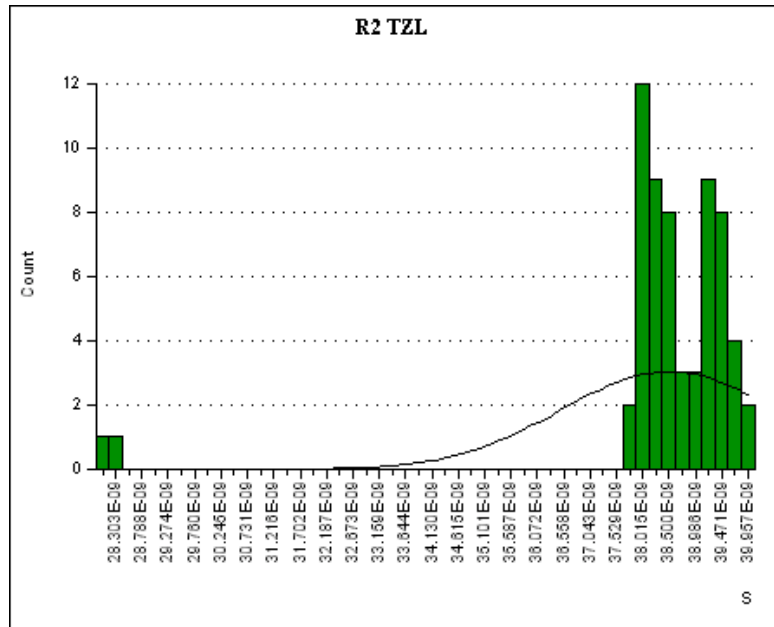
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.001, Test.Name=R2 TZL



Statistics: (S)

Max	39.957E-09	25%	38.103E-09	SpecHigh	N/A
Mean	38.396E-09	10%	38.010E-09	SpecLow	N/A
Min	28.060E-09	N	62	PctWithinSpec	N/A
Range	11.897E-09	Cp	N/A	c	
StdDev	1.975E-09	Cpl	N/A	PctDefSpec	N/A
W	0.4474	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	39.585E-09	Skew	-4.5974		
75%	39.213E-09	Kurtosis	22.6156		
Median	38.519E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

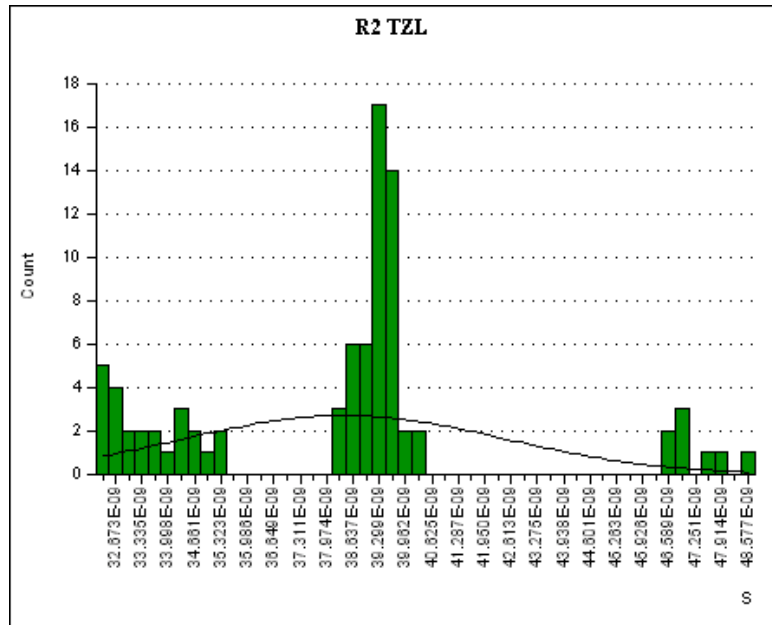
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.001, Test.Name=R2 TZL



Statistics: (S)

Max	48.577E-09	25%	34.607E-09	SpecHigh	N/A
Mean	38.367E-09	10%	32.813E-09	SpecLow	N/A
Min	32.341E-09	N	82	PctWithinSpec	N/A
Range	16.235E-09	Cp	N/A	c	
StdDev	3.972E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8515	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	40.365E-09	Skew	0.5601		
75%	39.610E-09	Kurtosis	0.5609		
Median	39.138E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

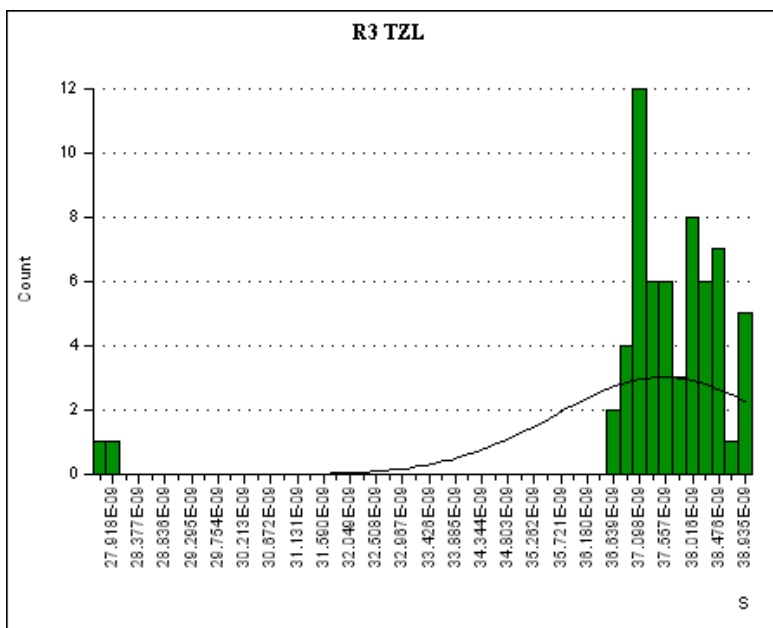
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.002, Test.Name=R3 TZL



Statistics: (S)

Max	38.935E-09	25%	37.174E-09	SpecHigh	N/A
Mean	37.408E-09	10%	36.895E-09	SpecLow	N/A
Min	27.688E-09	N	62	PctWithinSpec	N/A
Range	11.246E-09	Cp	N/A	PctDefSpec	N/A
StdDev	1.878E-09	Cpl	N/A	NWithinSpec	N/A
W	0.4836	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	38.563E-09	Skew	-4.4261		
75%	38.191E-09	Kurtosis	21.4499		
Median	37.589E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

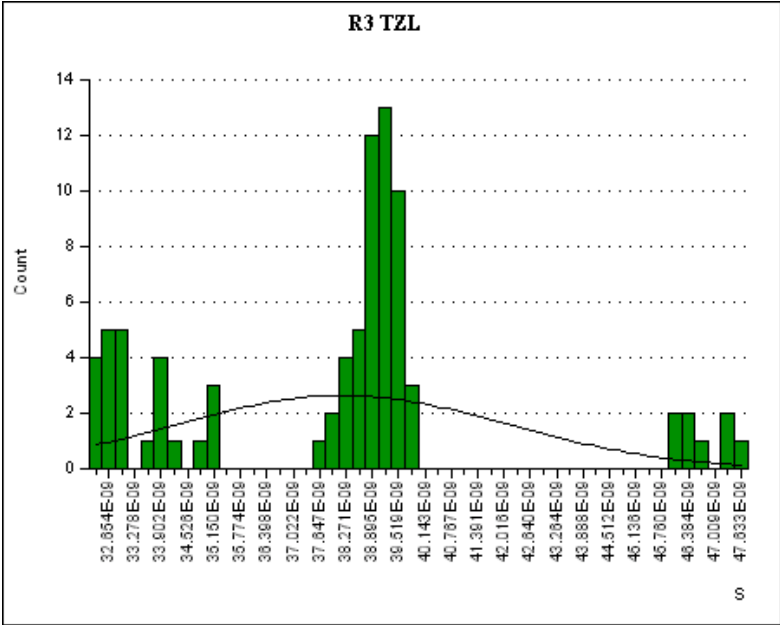
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.002, Test.Name=R3 TZL



Statistics: (S)

Max	47.633E-09	25%	34.796E-09	SpecHigh	N/A
Mean	38.135E-09	10%	32.719E-09	SpecLow	N/A
Min	32.341E-09	N	82	PctWithinSpec	N/A
Range	15.291E-09	Cp	N/A	c	
StdDev	3.861E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8534	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	39.893E-09	Skew	0.5134		
75%	39.421E-09	Kurtosis	0.4528		
Median	38.996E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

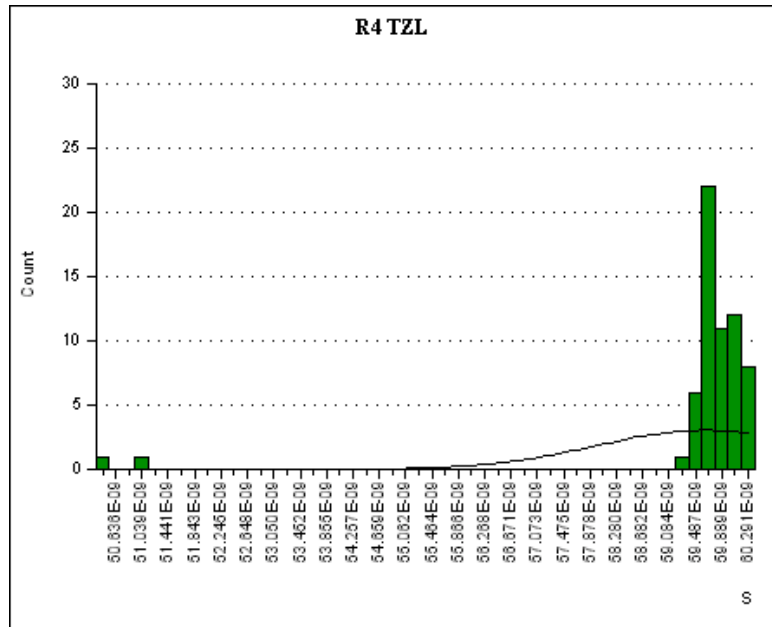
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=14.003, Test.Name=R4 TZL



Statistics: (S)

Max	60.291E-09	25%	59.641E-09	SpecHigh	N/A
Mean	59.540E-09	10%	59.451E-09	SpecLow	N/A
Min	50.435E-09	N	62	PctWithinSpec	N/A
Range	9.856E-09	Cp	N/A	PctDefSpec	N/A
StdDev	1.635E-09	Cpl	N/A	NWithinSpec	N/A
W	0.2933	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	60.198E-09	Skew	-5.2523		
75%	60.008E-09	Kurtosis	27.2050		
Median	59.778E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

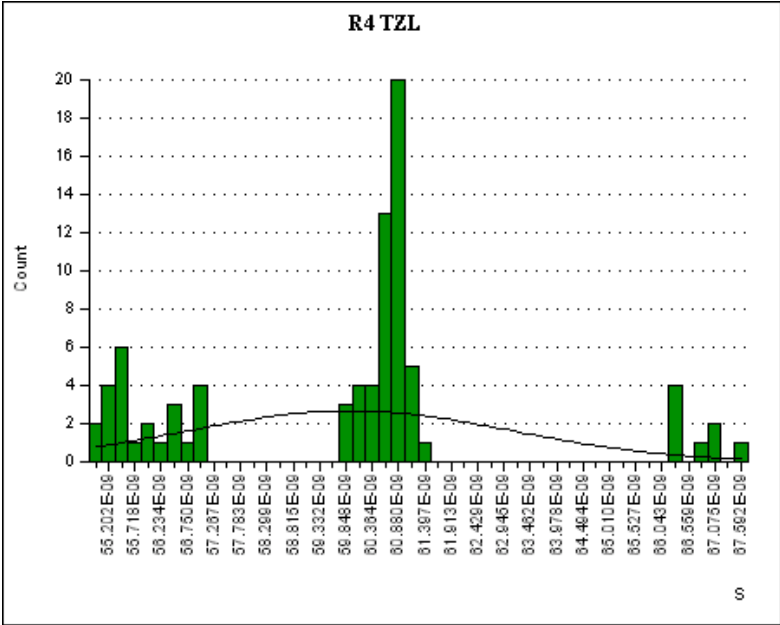
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.003, Test.Name=R4 TZL



Statistics: (S)

Max	67.592E-09	25%	56.926E-09	SpecHigh	N/A
Mean	59.892E-09	10%	55.415E-09	SpecLow	N/A
Min	54.943E-09	N	82	PctWithinSpec	N/A
Range	12.648E-09	Cp	N/A	c	
StdDev	3.157E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8519	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	61.268E-09	Skew	0.3969		
75%	60.984E-09	Kurtosis	0.2625		
Median	60.607E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

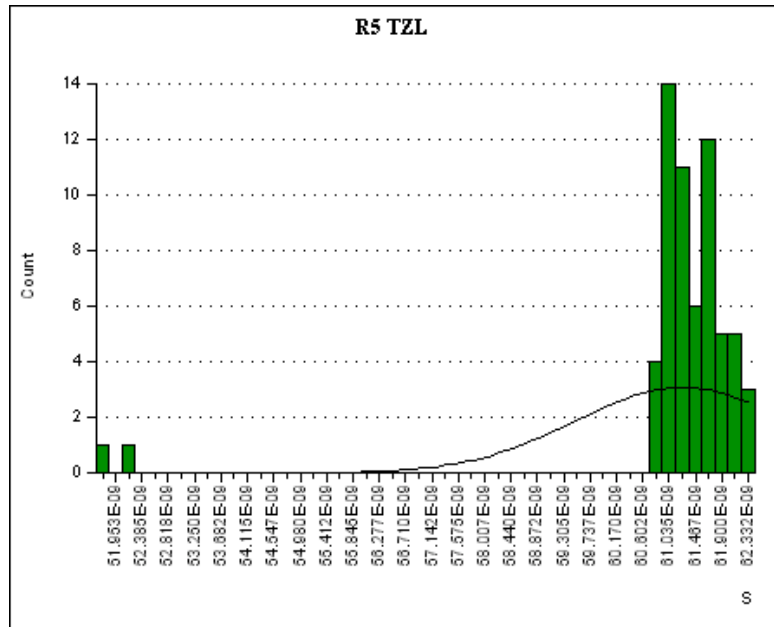
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=14.004, Test.Name=R5 TZL



Statistics: (S)

Max	62.332E-09	25%	61.128E-09	SpecHigh	N/A
Mean	61.165E-09	10%	60.942E-09	SpecLow	N/A
Min	51.736E-09	N	62	PctWithinSpec	N/A
Range	10.596E-09	Cp	N/A	PctDefSpec	N/A
StdDev	1.749E-09	Cpl	N/A	NWithinSpec	N/A
W	0.3725	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	62.146E-09	Skew	-4.9683		
75%	61.774E-09	Kurtosis	25.1640		
Median	61.361E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

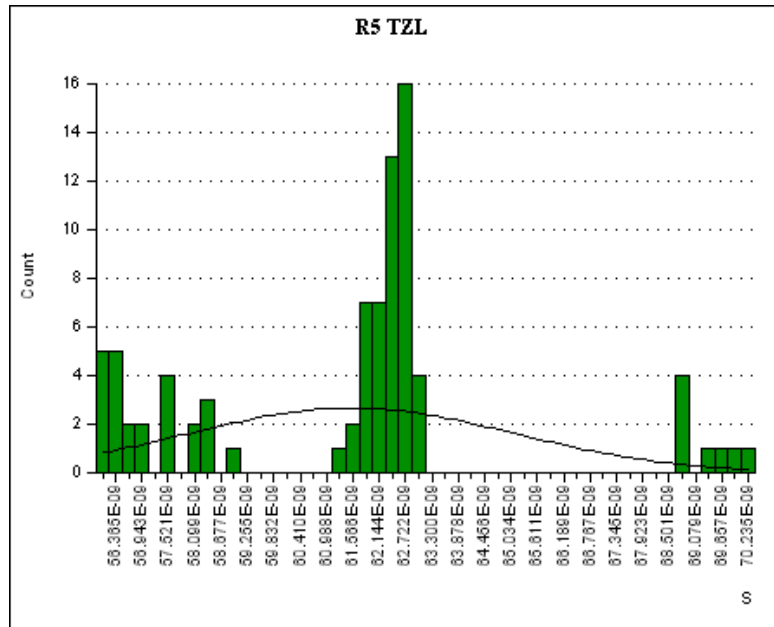
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.004, Test.Name=R5 TZL



Statistics: (S)

Max	70.235E-09	25%	58.247E-09	SpecHigh	N/A
Mean	61.487E-09	10%	56.454E-09	SpecLow	N/A
Min	56.076E-09	N	82	PctWithinSpec	N/A
Range	14.159E-09	Cp	N/A	PctDefSpec	N/A
StdDev	3.541E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8514	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	62.967E-09	Skew	0.4548		
75%	62.683E-09	Kurtosis	0.3705		
Median	62.259E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

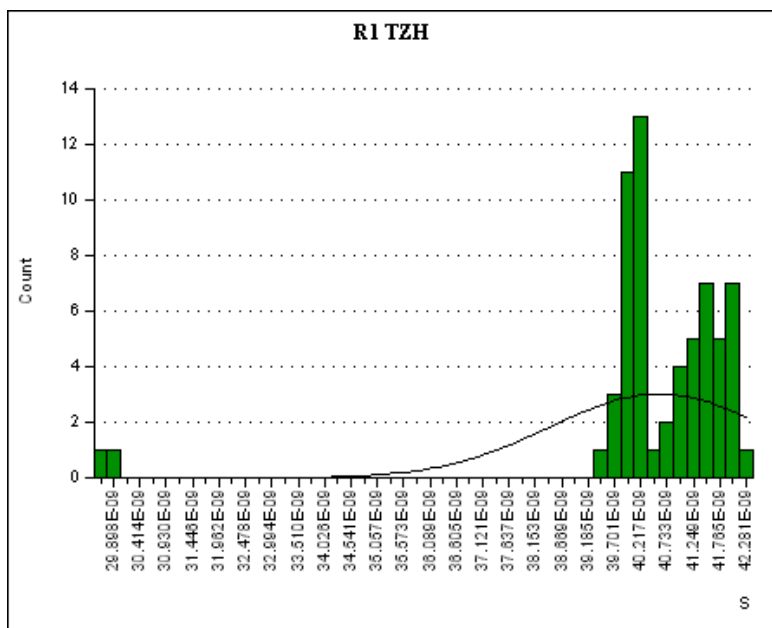
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.005, Test.Name=R1 TZh



Statistics: (S)

Max	42.281E-09	25%	40.056E-09	SpecHigh	N/A
Mean	40.467E-09	10%	39.870E-09	SpecLow	N/A
Min	29.640E-09	N	62	PctWithinSpec	N/A
Range	12.641E-09	Cp	N/A	c	
StdDev	2.114E-09	Cpl	N/A	PctDefSpec	N/A
W	0.5075	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	41.909E-09	Skew	-4.2350		
75%	41.537E-09	Kurtosis	20.1684		
Median	40.567E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

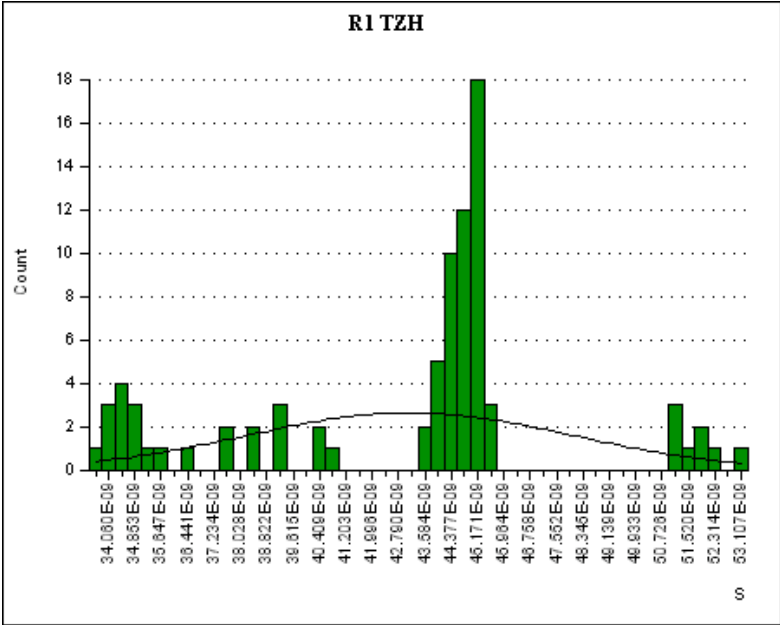
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.005, Test.Name=R1 TZh



Statistics: (S)

Max	53.107E-09	25%	39.326E-09	SpecHigh	N/A
Mean	43.051E-09	10%	34.796E-09	SpecLow	N/A
Min	33.663E-09	N	82	PctWithinSpec	N/A
Range	19.444E-09	Cp	N/A	c	
StdDev	4.873E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8628	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	45.651E-09	Skew	-0.3702		
75%	45.179E-09	Kurtosis	-0.1972		
Median	44.565E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

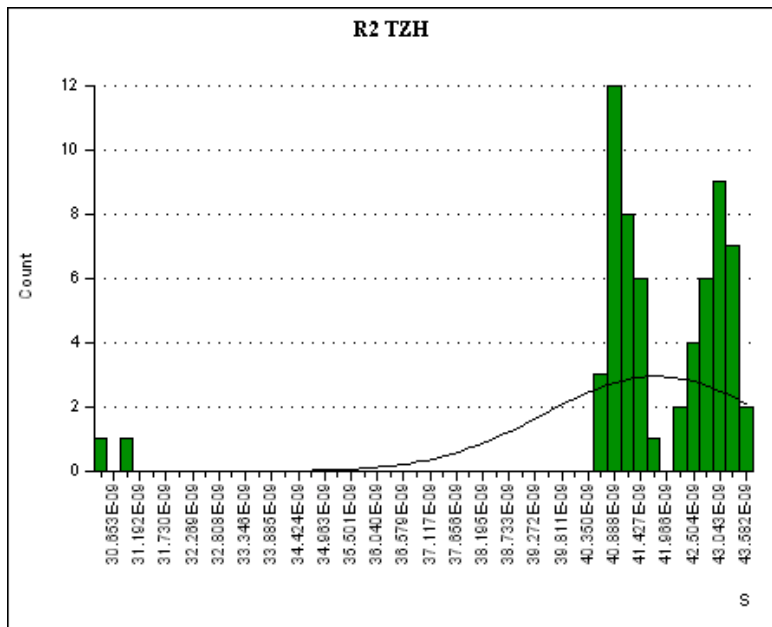
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=14.006, Test.Name=R2 TZh



Statistics: (S)

Max	43.582E-09	25%	40.986E-09	SpecHigh	N/A
Mean	41.630E-09	10%	40.800E-09	SpecLow	N/A
Min	30.384E-09	N	62	PctWithinSpec	N/A
Range	13.198E-09	Cp	N/A	PctDefSpec	N/A
StdDev	2.251E-09	Cpl	N/A	NWithinSpec	N/A
W	0.5584	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	43.303E-09	Skew	-3.8699		
75%	42.931E-09	Kurtosis	17.7392		
Median	41.590E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01.AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01.AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01.AT	-	0

Data: Raw Data

Stat limits applied

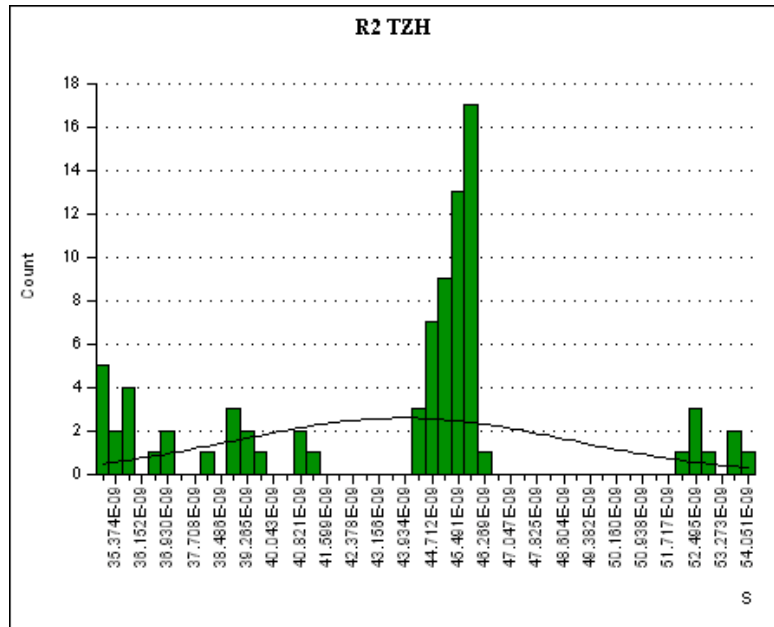
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.006, Test.Name=R2 TZh



Statistics: (S)

Max	54.051E-09	25%	39.610E-09	SpecHigh	N/A
Mean	43.778E-09	10%	35.740E-09	SpecLow	N/A
Min	34.984E-09	N	82	PctWithinSpec	N/A
Range	19.067E-09	Cp	N/A	PctDefSpec	N/A
StdDev	4.880E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8662	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	46.406E-09	Skew	-0.2014		
75%	45.839E-09	Kurtosis	-0.1905		
Median	45.273E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T		0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T		0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T		0

Data: Raw Data

Stat limits applied

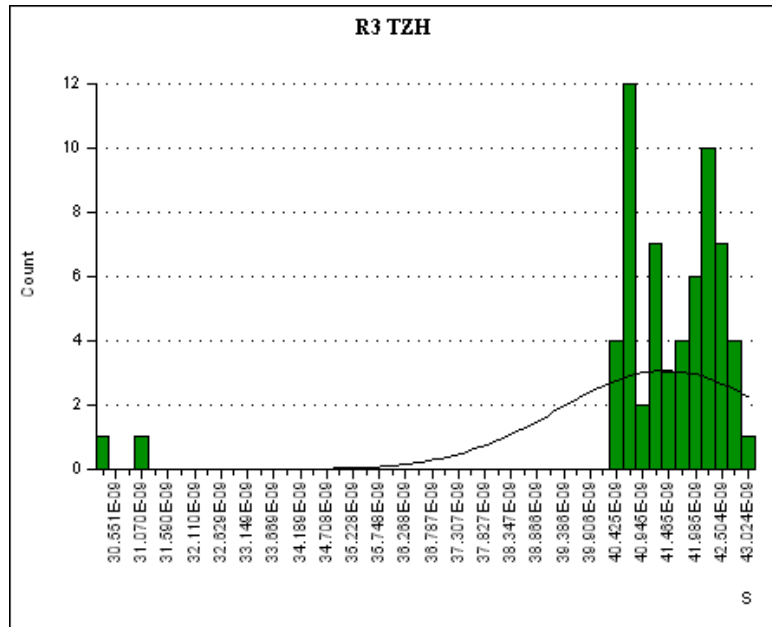
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.007, Test.Name=R3 TZh



Statistics: (S)

Max	43.024E-09	25%	40.707E-09	SpecHigh	N/A
Mean	41.288E-09	10%	40.614E-09	SpecLow	N/A
Min	30.291E-09	N	62	PctWithinSpec	N/A
Range	12.733E-09	Cp	N/A	PctDefSpec	N/A
StdDev	2.095E-09	Cpl	N/A	NWithinSpec	N/A
W	0.5011	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	42.559E-09	Skew	-4.3130		
75%	42.281E-09	Kurtosis	20.6616		
Median	41.726E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01.AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01.AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01.AT	-	0

Data: Raw Data

Stat limits applied

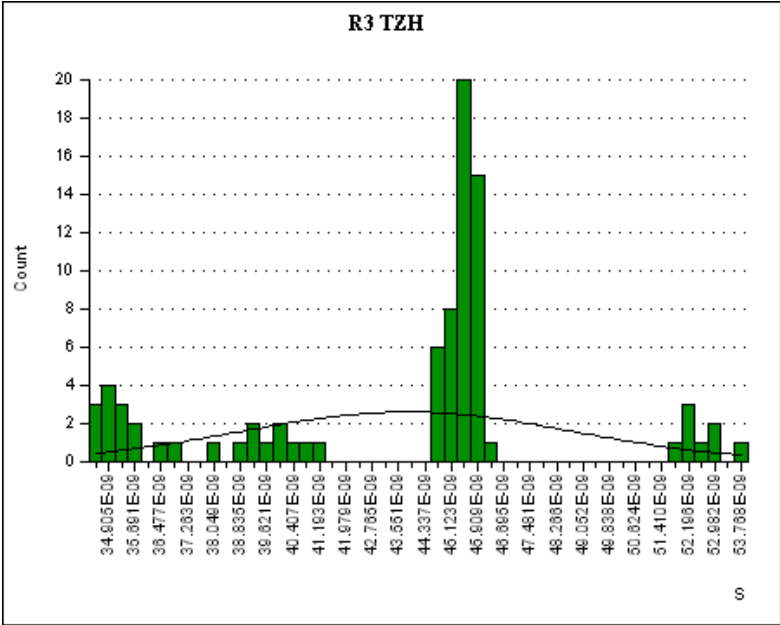
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.007, Test.Name=R3 TZh



Statistics: (S)

Max	53.768E-09	25%	40.081E-09	SpecHigh	N/A
Mean	43.725E-09	10%	35.173E-09	SpecLow	N/A
Min	34.512E-09	N	82	PctWithinSpec	N/A
Range	19.256E-09	Cp	N/A	c	
StdDev	4.922E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8516	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	46.122E-09	Skew	-0.3643		
75%	45.745E-09	Kurtosis	-0.2148		
Median	45.367E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

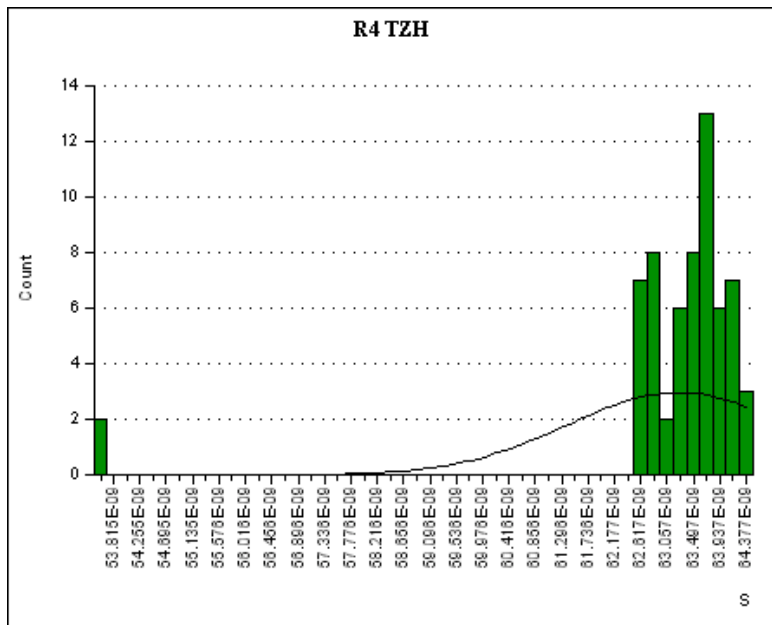
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=14.008, Test.Name=R4 TZh



Statistics: (S)

Max	64.377E-09	25%	62.895E-09	SpecHigh	N/A
Mean	63.150E-09	10%	62.709E-09	SpecLow	N/A
Min	53.595E-09	N	62	PctWithinSpec	N/A
Range	10.782E-09	Cp	N/A	c	
StdDev	1.834E-09	Cpl	N/A	PctDefSpec	N/A
W	0.4206	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	64.098E-09	Skew	-4.7483		
75%	63.912E-09	Kurtosis	23.5328		
Median	63.496E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

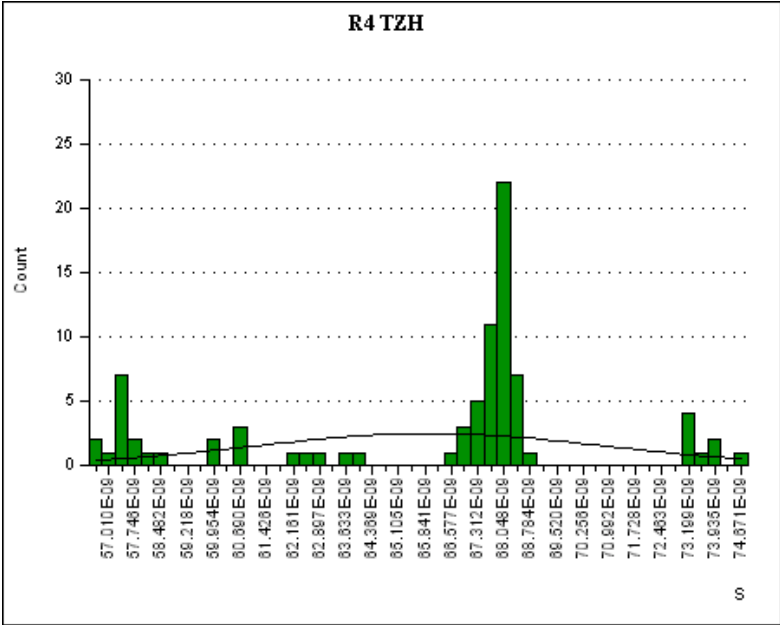
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.008, Test.Name=R4 TZh



Statistics: (S)

Max	74.671E-09	25%	62.683E-09	SpecHigh	N/A
Mean	65.886E-09	10%	57.492E-09	SpecLow	N/A
Min	56.642E-09	N	82	PctWithinSpec	N/A
Range	18.029E-09	Cp	N/A	c	
StdDev	4.835E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8386	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	68.819E-09	Skew	-0.5958		
75%	68.064E-09	Kurtosis	-0.4340		
Median	67.780E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

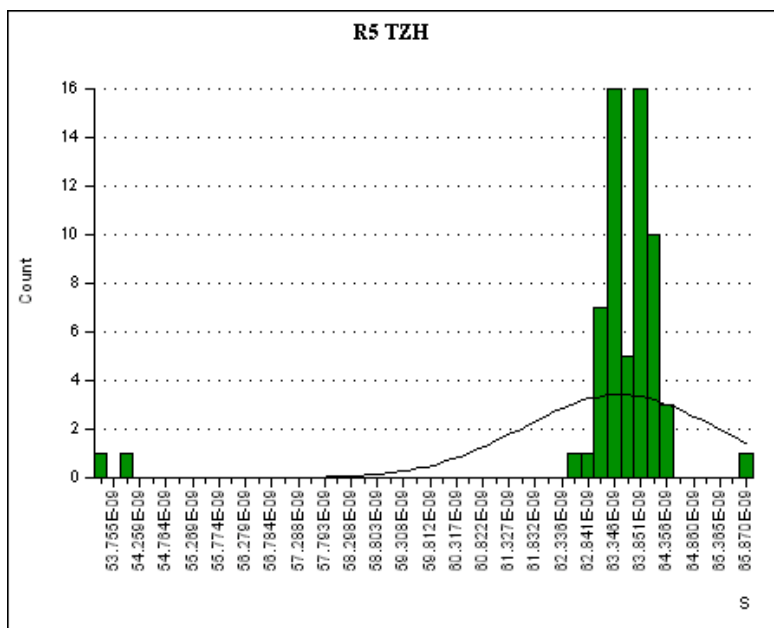
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=14.009, Test.Name=R5 TZh



Statistics: (S)

Max	65.870E-09	25%	63.360E-09	SpecHigh	N/A
Mean	63.340E-09	10%	63.174E-09	SpecLow	N/A
Min	53.502E-09	N	62	PctWithinSpec	N/A
Range	12.368E-09	Cp	N/A	PctDefSpec	N/A
StdDev	1.828E-09	Cpl	N/A	NWithinSpec	N/A
W	0.3844	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	64.098E-09	Skew	-4.8539		
75%	63.824E-09	Kurtosis	24.5760		
Median	63.592E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

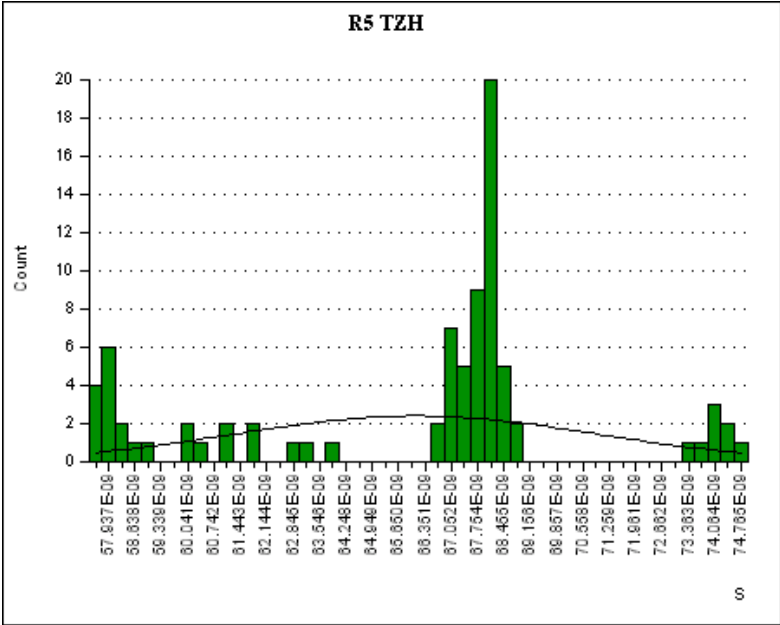
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.009, Test.Name=R5 TZh



Statistics: (S)

Max	74.765E-09	25%	61.834E-09	SpecHigh	N/A
Mean	66.023E-09	10%	57.964E-09	SpecLow	N/A
Min	57.586E-09	N	82	PctWithinSpec	N/A
Range	17.179E-09	Cp	N/A	c	
StdDev	4.750E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8508	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	68.724E-09	Skew	-0.4330		
75%	68.252E-09	Kurtosis	-0.4693		
Median	67.780E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

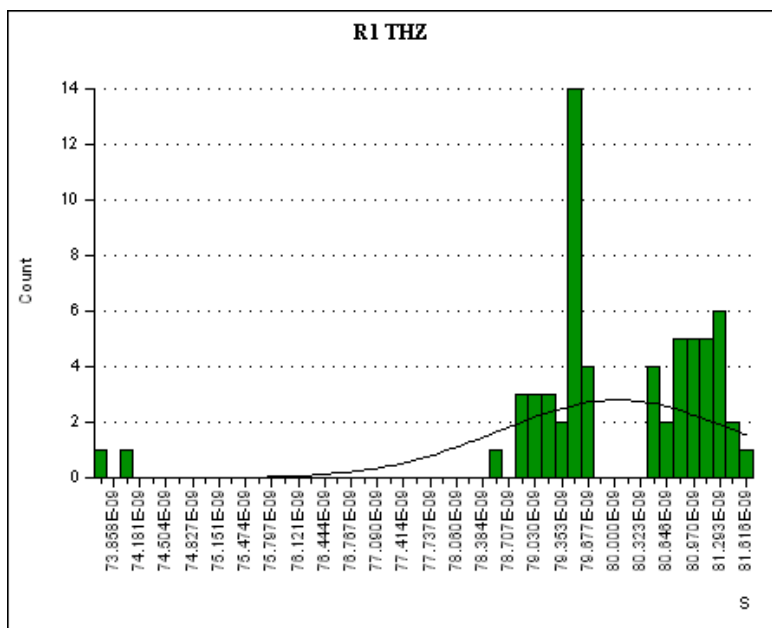
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=14.010, Test.Name=R1 THZ



Statistics: (S)

Max	81.616E-09	25%	79.459E-09	SpecHigh	N/A
Mean	79.972E-09	10%	78.994E-09	SpecLow	N/A
Min	73.696E-09	N	62	PctWithinSpec	N/A
Range	7.920E-09	Cp	N/A	PctDefSpec	N/A
StdDev	1.430E-09	Cpl	N/A	NWithinSpec	N/A
W	0.7368	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	81.244E-09	Skew	-2.5138		
75%	80.965E-09	Kurtosis	9.4523		
Median	79.737E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

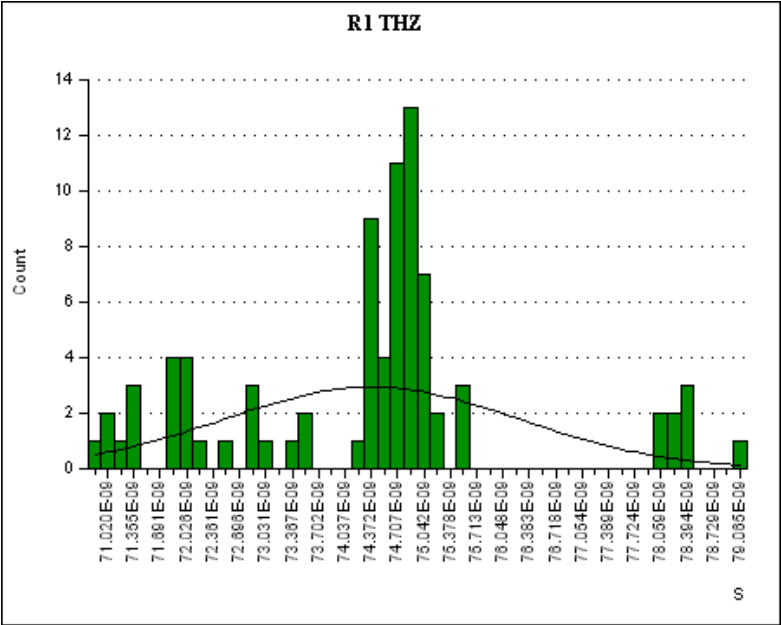
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.010, Test.Name=R1 THZ



Statistics: (S)

Max	79.065E-09	25%	73.024E-09	SpecHigh	N/A
Mean	74.345E-09	10%	71.891E-09	SpecLow	N/A
Min	70.853E-09	N	82	PctWithinSpec	N/A
Range	8.212E-09	Cp	N/A	c	
StdDev	1.859E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8961	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	75.572E-09	Skew	0.3278		
75%	74.911E-09	Kurtosis	0.4623		
Median	74.628E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

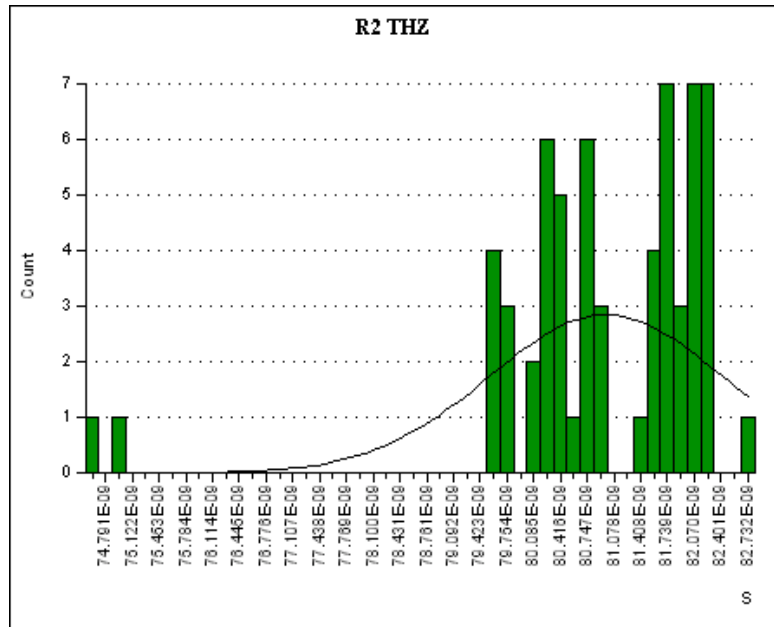
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=14.011, Test.Name=R2 THZ



Statistics: (S)

Max	82.732E-09	25%	80.202E-09	SpecHigh	N/A
Mean	80.916E-09	10%	79.737E-09	SpecLow	N/A
Min	74.625E-09	N	62	PctWithinSpec	N/A
Range	8.107E-09	Cp	N/A	c	
StdDev	1.440E-09	Cpl	N/A	PctDefSpec	N/A
W	0.7475	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	82.174E-09	Skew	-2.5132		
75%	81.895E-09	Kurtosis	9.2122		
Median	80.899E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

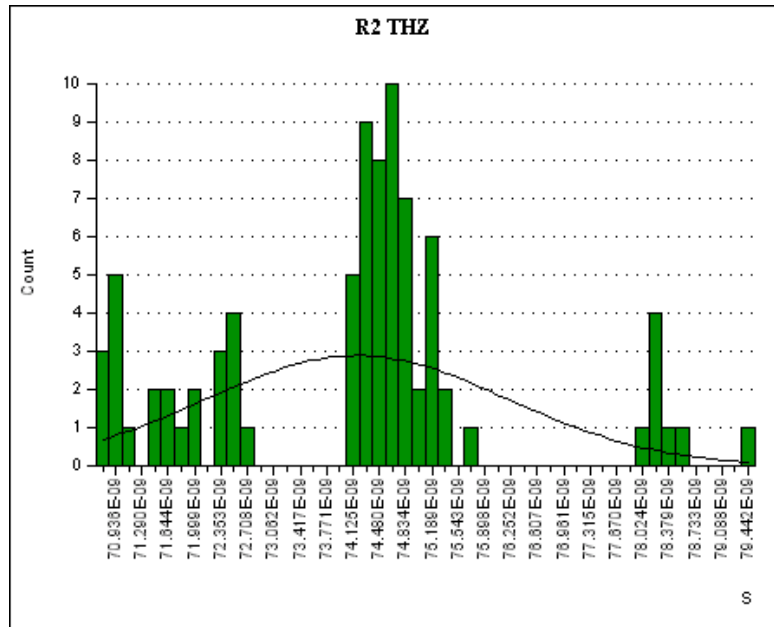
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.011, Test.Name=R2 THZ



Statistics: (S)

Max	79.442E-09	25%	72.552E-09	SpecHigh	N/A
Mean	74.149E-09	10%	71.136E-09	SpecLow	N/A
Min	70.758E-09	N	82	PctWithinSpec	N/A
Range	8.684E-09	Cp	N/A	PctDefSpec	N/A
StdDev	2.007E-09	Cpl	N/A	NWithinSpec	N/A
W	0.9029	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	75.667E-09	Skew	0.2780		
75%	74.911E-09	Kurtosis	0.2600		
Median	74.487E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

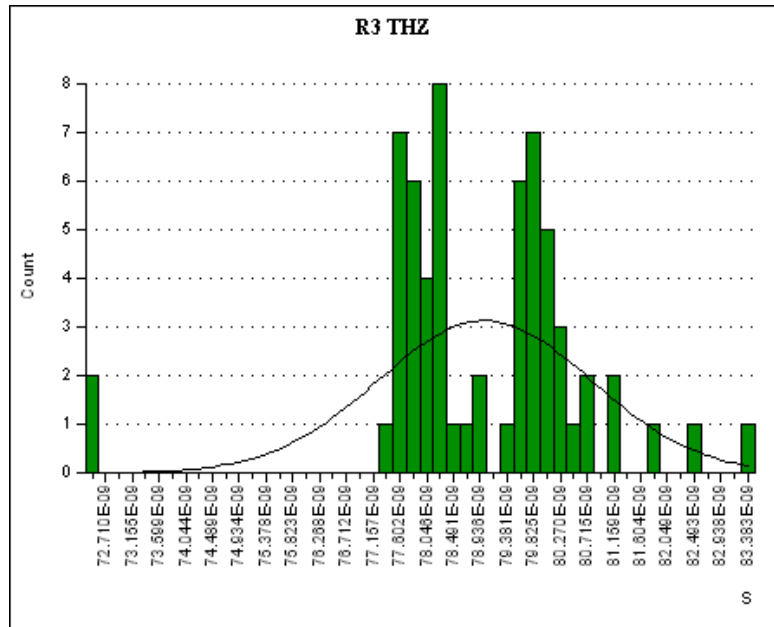
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.012, Test.Name=R3 THZ



Statistics: (S)

Max	83.383E-09	25%	77.879E-09	SpecHigh	N/A
Mean	78.940E-09	10%	77.693E-09	SpecLow	N/A
Min	72.488E-09	N	62	PctWithinSpec	N/A
Range	10.895E-09	Cp	N/A	c	
StdDev	1.755E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8681	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	80.687E-09	Skew	-1.0906		
75%	79.943E-09	Kurtosis	4.6830		
Median	78.901E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01.AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01.AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01.AT	-	0

Data: Raw Data

Stat limits applied

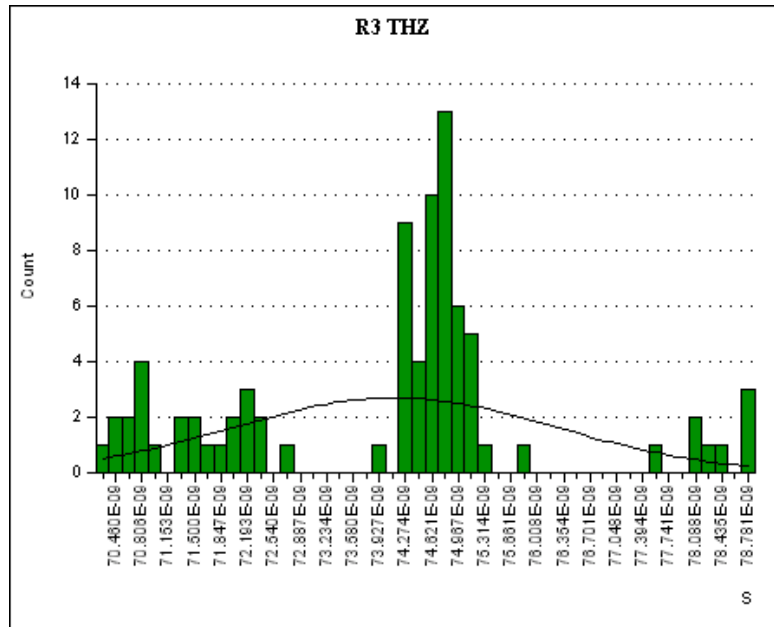
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.012, Test.Name=R3 THZ



Statistics: (S)

Max	78.781E-09	25%	72.174E-09	SpecHigh	N/A
Mean	74.093E-09	10%	70.853E-09	SpecLow	N/A
Min	70.286E-09	N	82	PctWithinSpec	N/A
Range	8.495E-09	Cp	N/A	c	
StdDev	2.098E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8955	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	75.761E-09	Skew	0.1303		
75%	74.911E-09	Kurtosis	0.0474		
Median	74.534E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

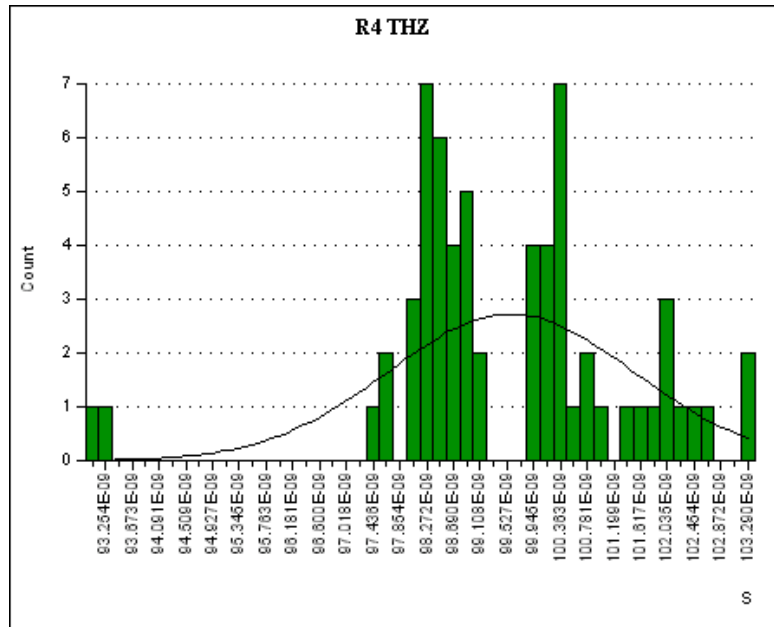
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.013, Test.Name=R4 THZ



Statistics: (S)

Max	103.290E-09	25%	98.436E-09	SpecHigh	N/A
Mean	99.519E-09	10%	97.972E-09	SpecLow	N/A
Min	93.045E-09	N	62	PctWithinSpec	N/A
Range	10.244E-09	Cp	N/A	c	
StdDev	1.901E-09	Cpl	N/A	PctDefSpec	N/A
W	0.9104	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0003	Cpk	N/A	NOutsideSpec	N/A
90%	102.081E-09	Skew	-0.7249		
75%	100.408E-09	Kurtosis	2.5554		
Median	99.087E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

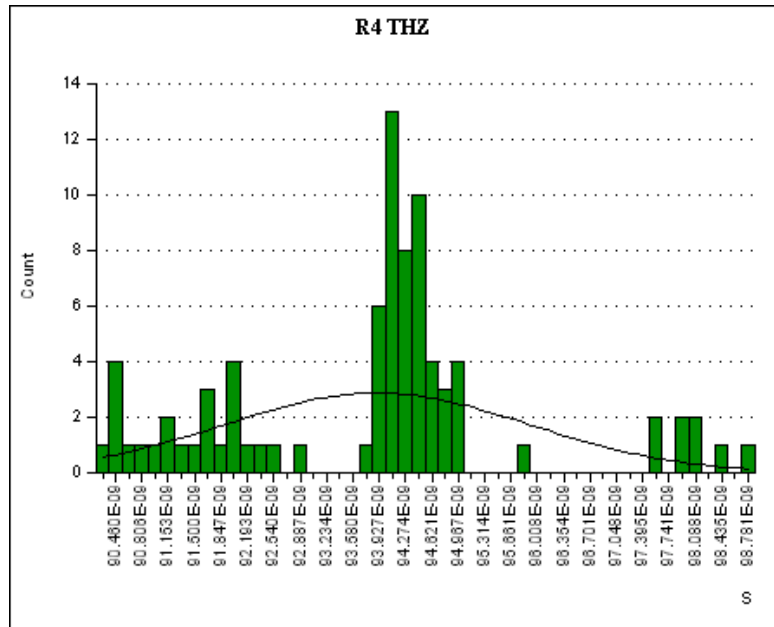
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.013, Test.Name=R4 THZ



Statistics: (S)

Max	98.781E-09	25%	92.269E-09	SpecHigh	N/A
Mean	93.867E-09	10%	91.136E-09	SpecLow	N/A
Min	90.286E-09	N	82	PctWithinSpec	N/A
Range	8.495E-09	Cp	N/A	PctDefSpec	N/A
StdDev	1.971E-09	Cpl	N/A	NWithinSpec	N/A
W	0.9061	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	95.761E-09	Skew	0.2968		
75%	94.534E-09	Kurtosis	0.3212		
Median	94.156E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

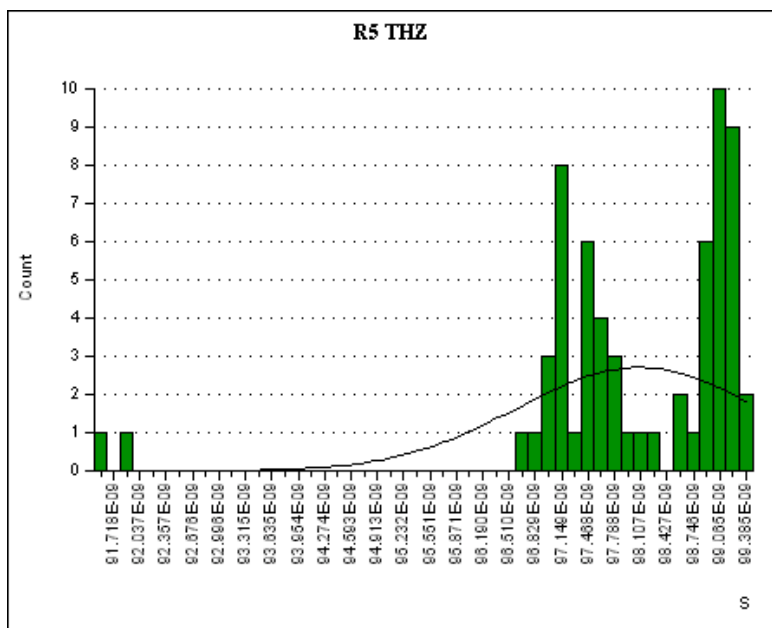
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.014, Test.Name=R5 THZ



Statistics: (S)

Max	99.385E-09	25%	97.321E-09	SpecHigh	N/A
Mean	98.020E-09	10%	96.949E-09	SpecLow	N/A
Min	91.558E-09	N	62	PctWithinSpec	N/A
Range	7.827E-09	Cp	N/A	c	
StdDev	1.460E-09	Cpl	N/A	PctDefSpec	N/A
W	0.7117	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	99.292E-09	Skew	-2.6283		
75%	99.106E-09	Kurtosis	9.8334		
Median	98.204E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

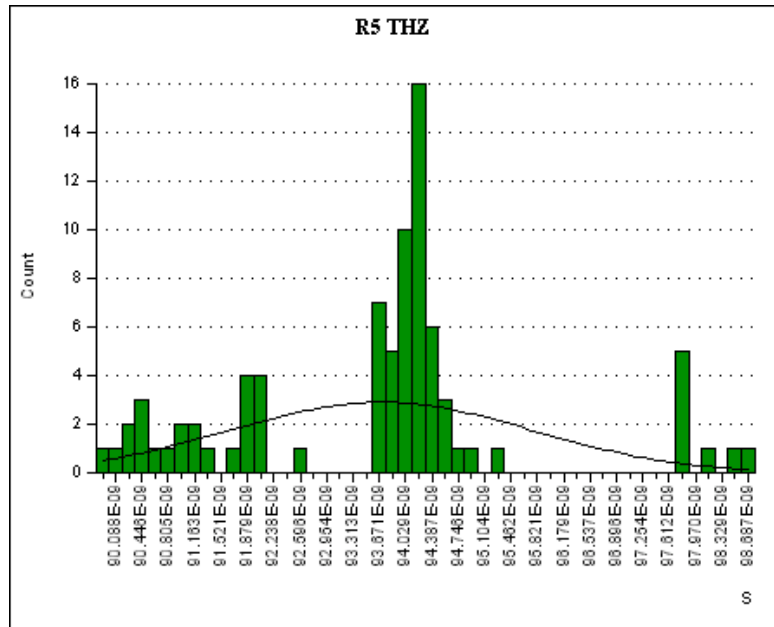
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.014, Test.Name=R5 THZ



Statistics: (S)

Max	98.687E-09	25%	92.080E-09	SpecHigh	N/A
Mean	93.664E-09	10%	90.758E-09	SpecLow	N/A
Min	89.909E-09	N	82	PctWithinSpec	N/A
Range	8.778E-09	Cp	N/A	PctDefSpec	N/A
StdDev	2.014E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8924	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	95.195E-09	Skew	0.3720		
75%	94.251E-09	Kurtosis	0.4743		
Median	94.062E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

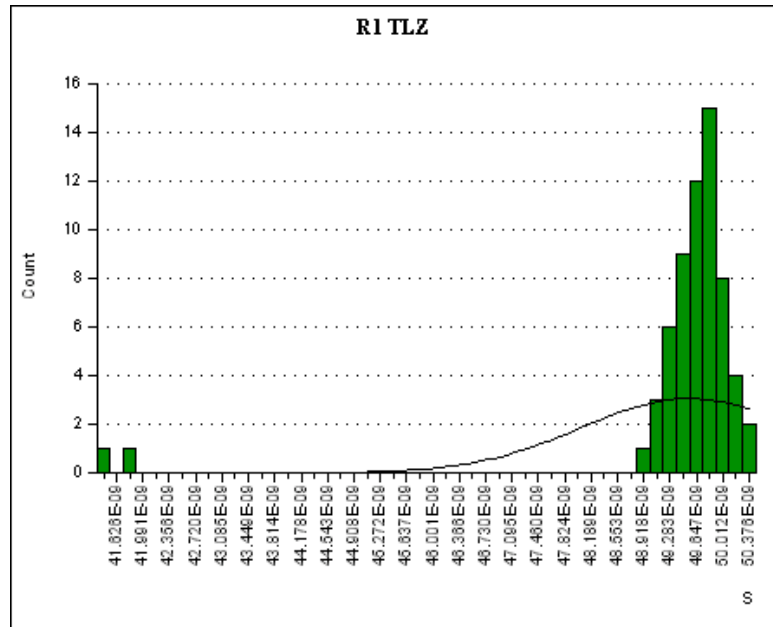
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.015, Test.Name=R1 TLZ



Statistics: (S)

Max	50.376E-09	25%	49.437E-09	SpecHigh	N/A
Mean	49.460E-09	10%	49.251E-09	SpecLow	N/A
Min	41.444E-09	N	62	PctWithinSpec	N/A
Range	8.932E-09	Cp	N/A	c	
StdDev	1.476E-09	Cpl	N/A	PctDefSpec	N/A
W	0.3589	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	50.097E-09	Skew	-5.0327		
75%	49.911E-09	Kurtosis	25.5710		
Median	49.725E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

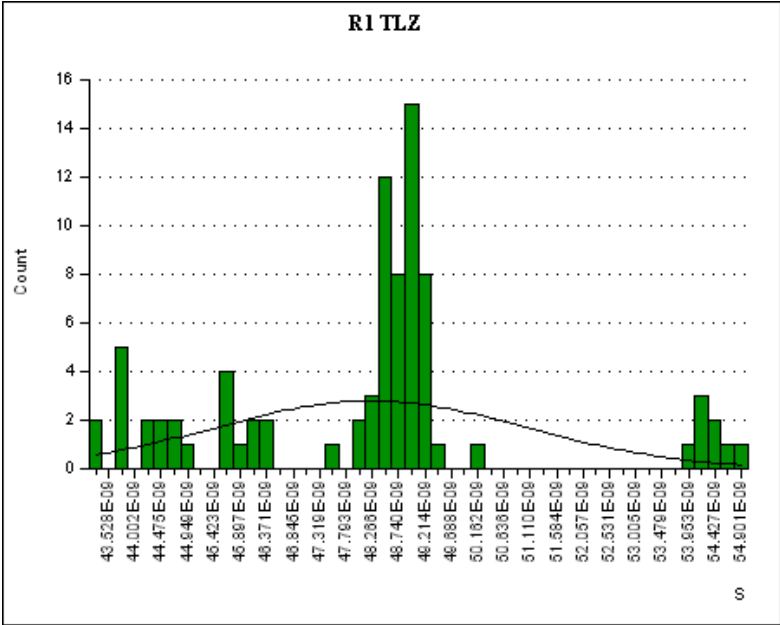
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.015, Test.Name=R1 TLZ



Statistics: (S)

Max	54.901E-09	25%	46.028E-09	SpecHigh	N/A
Mean	48.200E-09	10%	44.235E-09	SpecLow	N/A
Min	43.291E-09	N	82	PctWithinSpec	N/A
Range	11.610E-09	Cp	N/A	c	
StdDev	2.772E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8716	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	50.087E-09	Skew	0.4545		
75%	49.049E-09	Kurtosis	0.6033		
Median	48.624E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

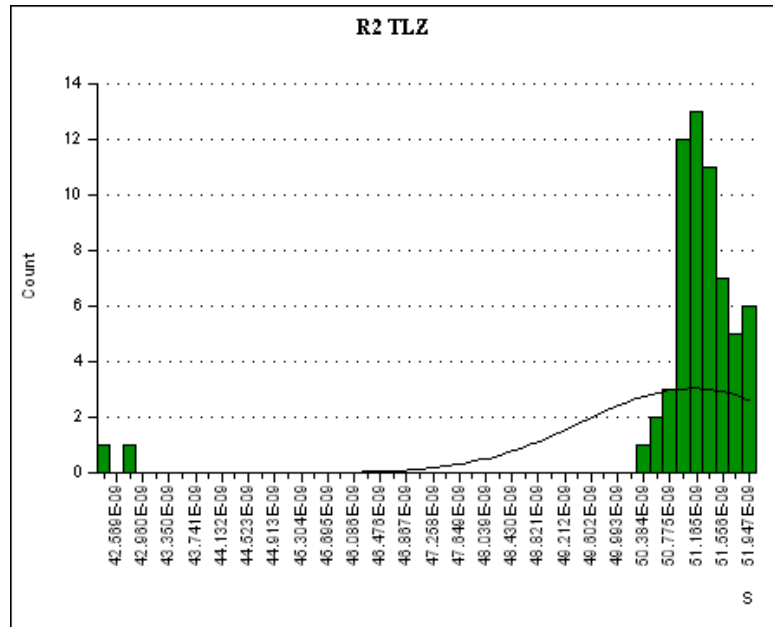
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=14.016, Test.Name=R2 TLZ



Statistics: (S)

Max	51.947E-09	25%	51.027E-09	SpecHigh	N/A
Mean	51.000E-09	10%	50.832E-09	SpecLow	N/A
Min	42.374E-09	N	62	PctWithinSpec	N/A
Range	9.573E-09	Cp	N/A	PctDefSpec	N/A
StdDev	1.591E-09	Cpl	N/A	NWithinSpec	N/A
W	0.3558	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	51.771E-09	Skew	-5.0361		
75%	51.482E-09	Kurtosis	25.6189		
Median	51.213E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

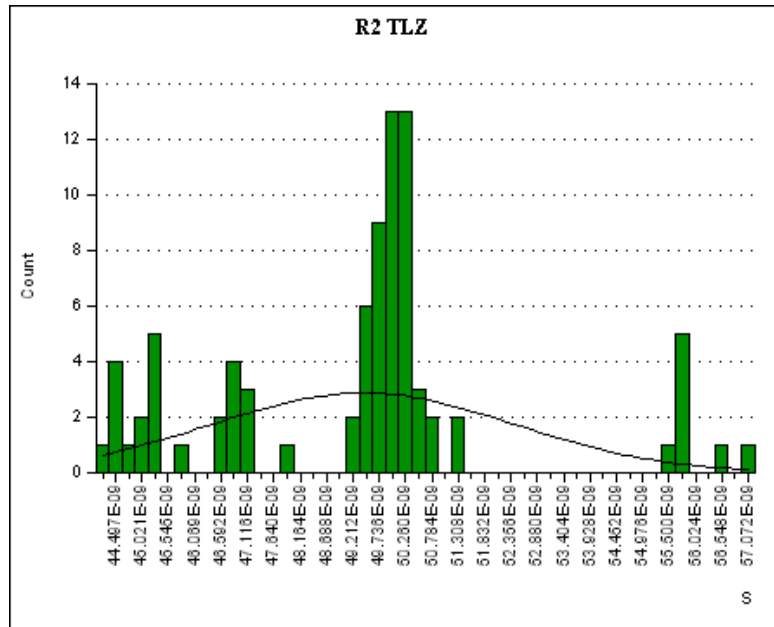
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.016, Test.Name=R2 TLZ



Statistics: (S)

Max	57.072E-09	25%	47.066E-09	SpecHigh	N/A
Mean	49.373E-09	10%	45.179E-09	SpecLow	N/A
Min	44.235E-09	N	82	PctWithinSpec	N/A
Range	12.837E-09	Cp	N/A	PctDefSpec	N/A
StdDev	2.979E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8777	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	51.408E-09	Skew	0.4509		
75%	50.276E-09	Kurtosis	0.5572		
Median	49.851E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

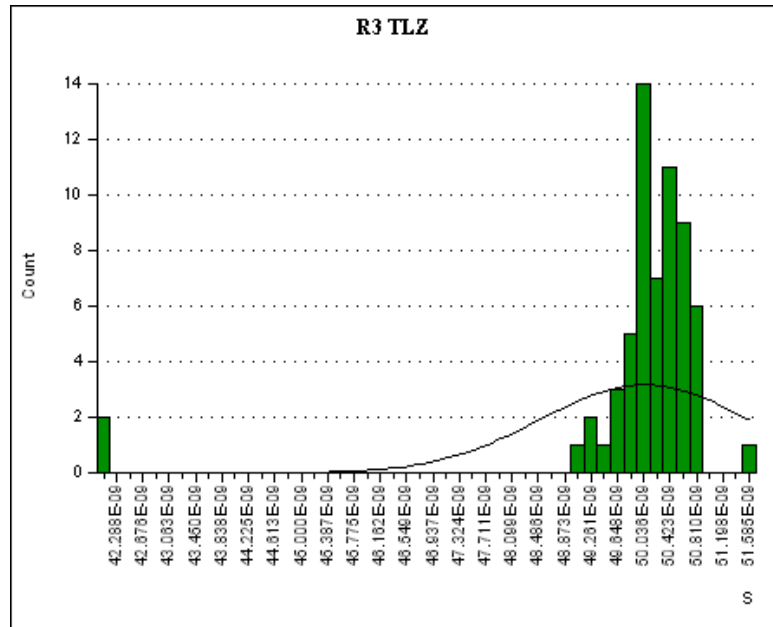
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.017, Test.Name=R3 TLZ



Statistics: (S)

Max	51.585E-09	25%	49.995E-09	SpecHigh	N/A
Mean	49.967E-09	10%	49.623E-09	SpecLow	N/A
Min	42.095E-09	N	62	PctWithinSpec	N/A
Range	9.490E-09	Cp	N/A	c	
StdDev	1.508E-09	Cpl	N/A	PctDefSpec	N/A
W	0.4146	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	50.739E-09	Skew	-4.7715		
75%	50.553E-09	Kurtosis	23.7347		
Median	50.190E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

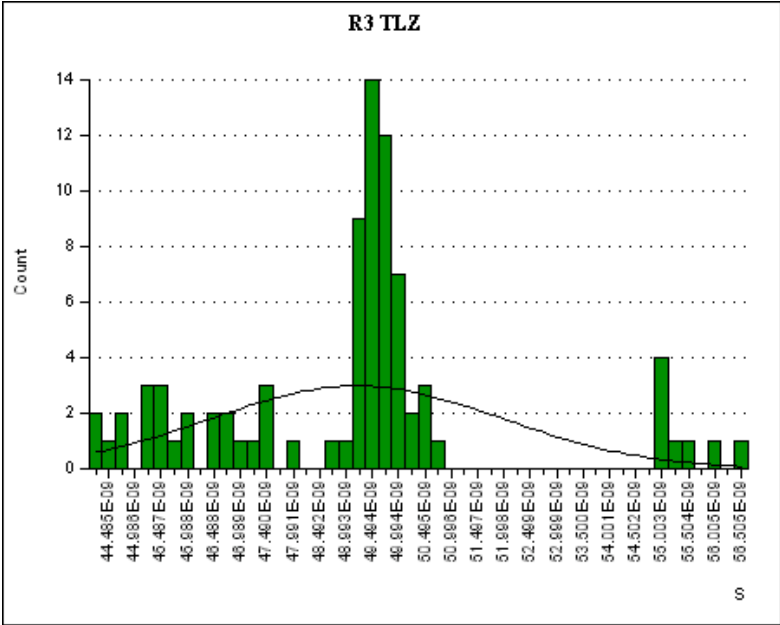
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.017, Test.Name=R3 TLZ



Statistics: (S)

Max	56.505E-09	25%	47.444E-09	SpecHigh	N/A
Mean	49.153E-09	10%	45.367E-09	SpecLow	N/A
Min	44.235E-09	N	82	PctWithinSpec	N/A
Range	12.271E-09	Cp	N/A	c	
StdDev	2.740E-09	Cpl	N/A	PctDefSpec	N/A
W	0.8728	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	50.748E-09	Skew	0.5886		
75%	49.898E-09	Kurtosis	0.8964		
Median	49.568E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

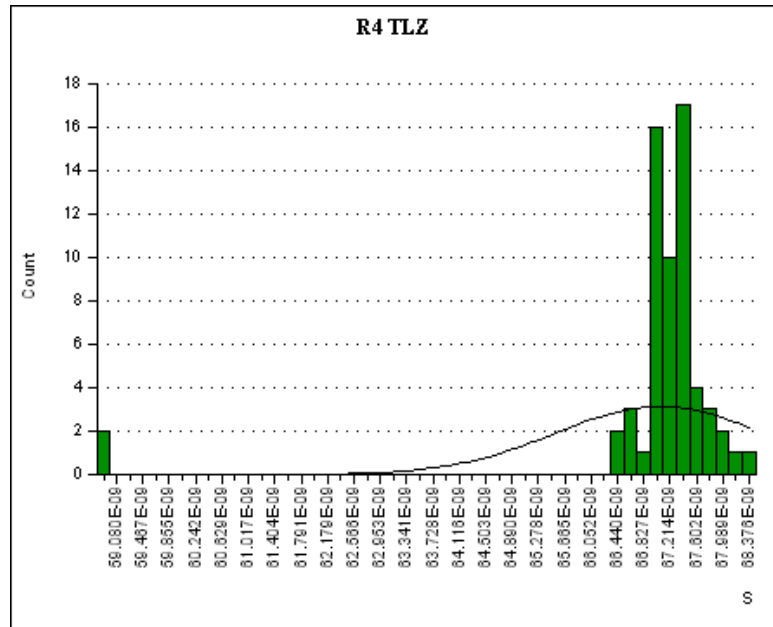
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=14.018, Test.Name=R4 TLZ



Statistics: (S)

Max	68.376E-09	25%	66.973E-09	SpecHigh	N/A
Mean	66.985E-09	10%	66.601E-09	SpecLow	N/A
Min	58.886E-09	N	62	PctWithinSpec	N/A
Range	9.490E-09	Cp	N/A	c	
StdDev	1.527E-09	Cpl	N/A	PctDefSpec	N/A
W	0.3822	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	67.725E-09	Skew	-4.9219		
75%	67.447E-09	Kurtosis	24.8238		
Median	67.210E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

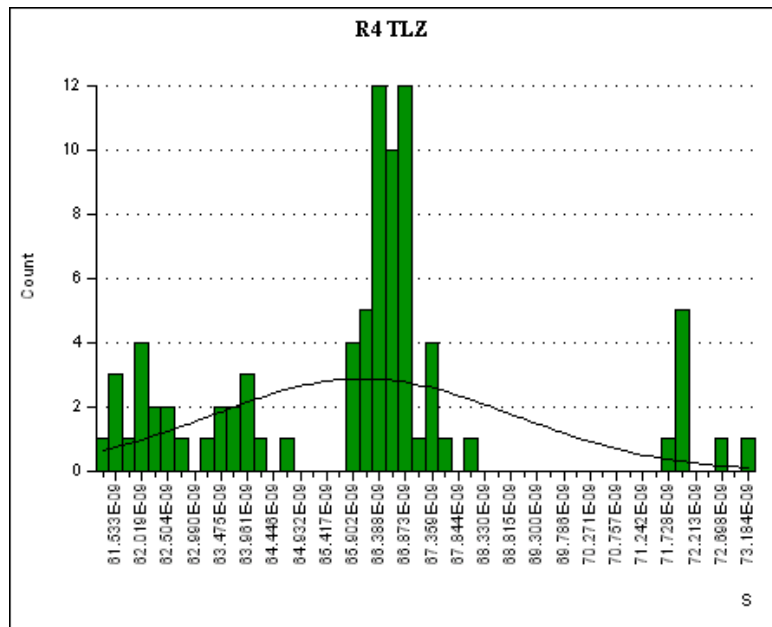
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.018, Test.Name=R4 TLZ



Statistics: (S)

Max	73.184E-09	25%	63.934E-09	SpecHigh	N/A
Mean	66.038E-09	10%	62.046E-09	SpecLow	N/A
Min	61.291E-09	N	82	PctWithinSpec	N/A
Range	11.893E-09	Cp	N/A	PctDefSpec	N/A
StdDev	2.748E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8827	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	68.087E-09	Skew	0.4883		
75%	66.954E-09	Kurtosis	0.5974		
Median	66.388E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

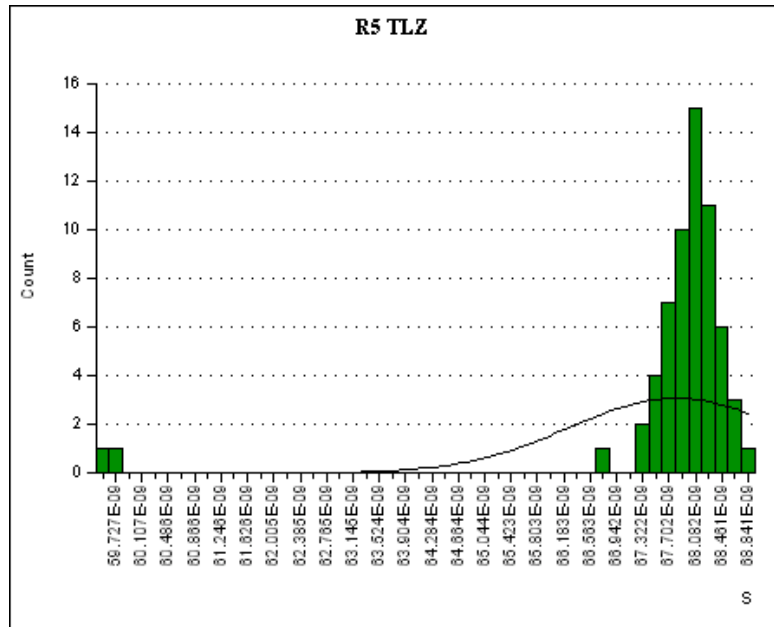
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.019, Test.Name=R5 TLZ



Statistics: (S)

Max	68.841E-09	25%	67.716E-09	SpecHigh	N/A
Mean	67.727E-09	10%	67.437E-09	SpecLow	N/A
Min	59.537E-09	N	62	PctWithinSpec	N/A
Range	9.304E-09	Cp	N/A	PctDefSpec	N/A
StdDev	1.526E-09	Cpl	N/A	NWithinSpec	N/A
W	0.3758	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	68.376E-09	Skew	-4.9521		
75%	68.274E-09	Kurtosis	24.9520		
Median	68.000E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

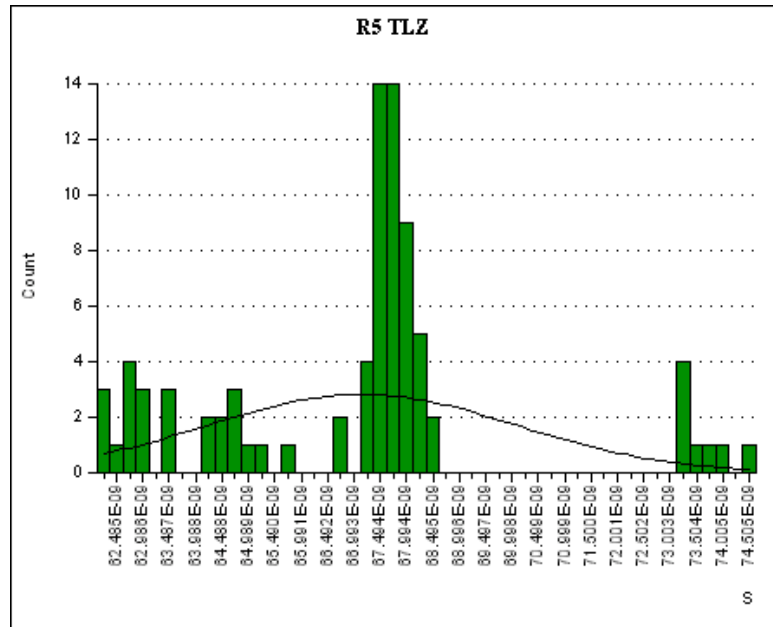
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=14.019, Test.Name=R5 TLZ



Statistics: (S)

Max	74.505E-09	25%	64.783E-09	SpecHigh	N/A
Mean	67.105E-09	10%	62.990E-09	SpecLow	N/A
Min	62.235E-09	N	82	PctWithinSpec	N/A
Range	12.271E-09	Cp	N/A	PctDefSpec	N/A
StdDev	2.904E-09	Cpl	N/A	NWithinSpec	N/A
W	0.8666	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	68.559E-09	Skew	0.5158		
75%	67.898E-09	Kurtosis	0.6479		
Median	67.615E-09				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

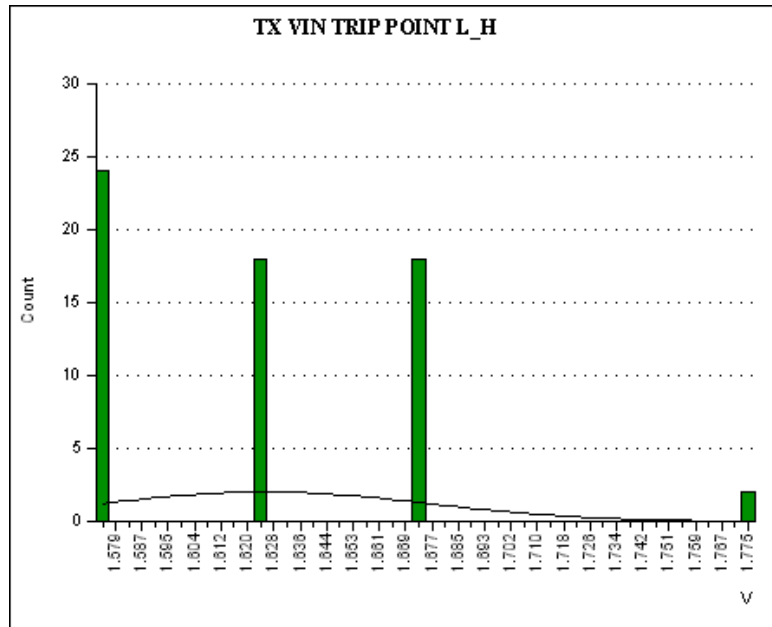
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.000, Test.Name=TX VIN TRIP POINT L_H



Statistics: (V)

Max	1.775	25%	1.575	SpecHigh	N/A
Mean	1.625	10%	1.575	SpecLow	N/A
Min	1.575	N	62	PctWithinSpec	N/A
Range	200.000E-03	Cp	N/A	PctDefSpec	N/A
StdDev	49.588E-03	Cpl	N/A	NWithinSpec	N/A
W	0.8147	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.675	Skew	0.8335		
75%	1.675	Kurtosis	0.6607		
Median	1.625				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

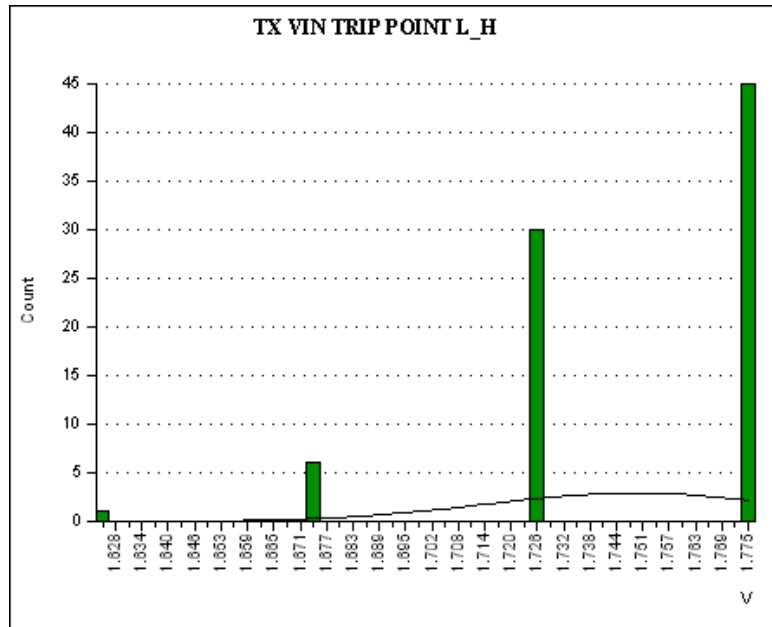
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.000, Test.Name=TX VIN TRIP POINT L_H



Statistics: (V)

Max	1.775	25%	1.725	SpecHigh	N/A
Mean	1.748	10%	1.725	SpecLow	N/A
Min	1.625	N	82	PctWithinSpec	N/A
Range	150.001E-03	Cp	N/A	PctDefSpec	N/A
StdDev	34.384E-03	Cpl	N/A	NWithinSpec	N/A
W	0.7316	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.775	Skew	-1.1045		
75%	1.775	Kurtosis	0.9305		
Median	1.775				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

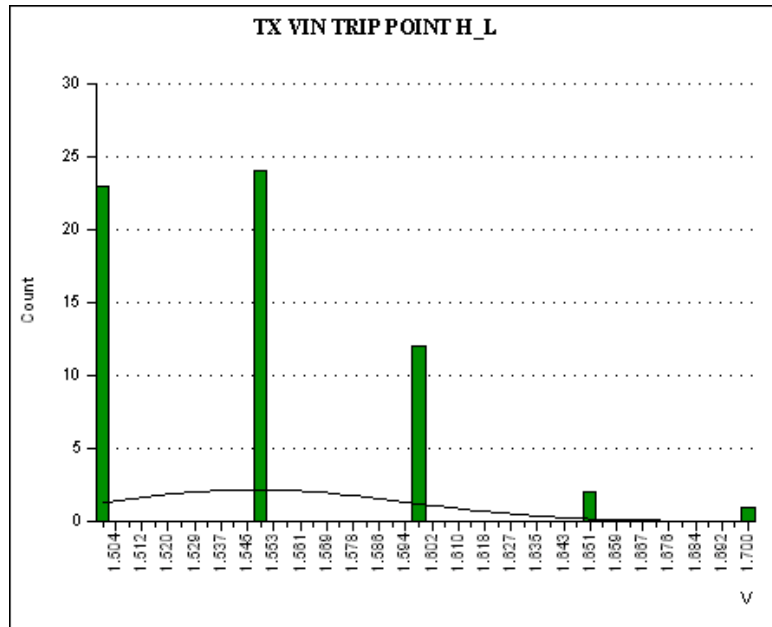
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.001, Test.Name=TX VIN TRIP POINT H_L



Statistics: (V)

Max	1.700	25%	1.500	SpecHigh	N/A
Mean	1.547	10%	1.500	SpecLow	N/A
Min	1.500	N	62	PctWithinSpec	N/A
Range	200.000E-03	Cp	N/A	PctDefSpec	N/A
StdDev	46.049E-03	Cpl	N/A	NWithinSpec	N/A
W	0.8305	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.600	Skew	0.9114		
75%	1.550	Kurtosis	0.8076		
Median	1.550				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

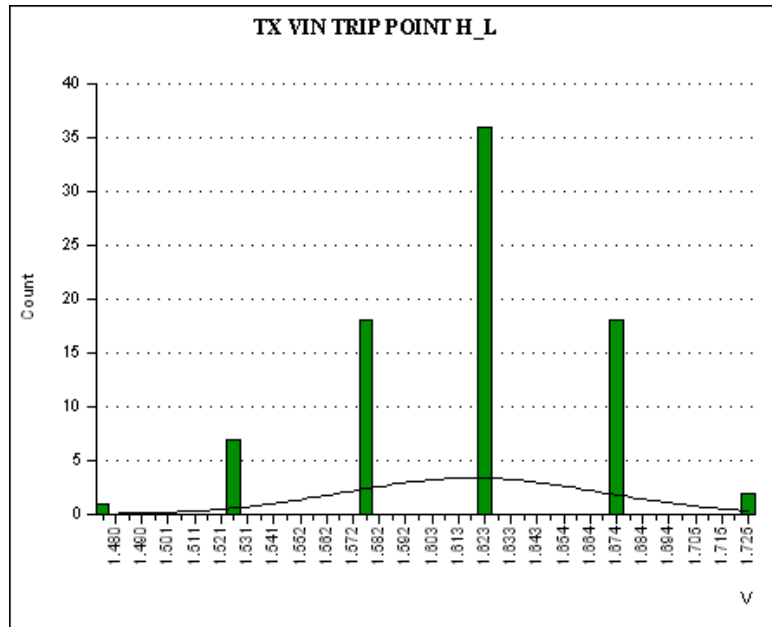
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N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.001, Test.Name=TX VIN TRIP POINT H_L



Statistics: (V)

Max	1.725	25%	1.575	SpecHigh	N/A
Mean	1.617	10%	1.575	SpecLow	N/A
Min	1.475	N	82	PctWithinSpec	N/A
Range	250.000E-03	Cp	N/A	PctDefSpec	N/A
StdDev	49.360E-03	Cpl	N/A	NWithinSpec	N/A
W	0.9035	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.675	Skew	-0.3832		
75%	1.625	Kurtosis	0.1132		
Median	1.625				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

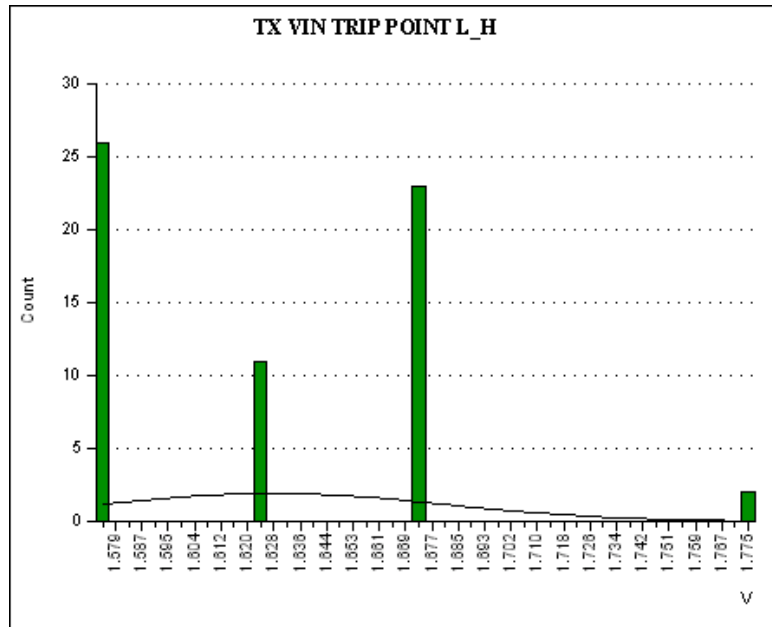
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.002, Test.Name=TX VIN TRIP POINT L_H



Statistics: (V)

Max	1.775	25%	1.575	SpecHigh	N/A
Mean	1.627	10%	1.575	SpecLow	N/A
Min	1.575	N	62	PctWithinSpec	N/A
Range	200.000E-03	Cp	N/A	PctDefSpec	N/A
StdDev	52.344E-03	Cpl	N/A	NWithinSpec	N/A
W	0.7921	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.675	Skew	0.6096		
75%	1.675	Kurtosis	-0.1104		
Median	1.625				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

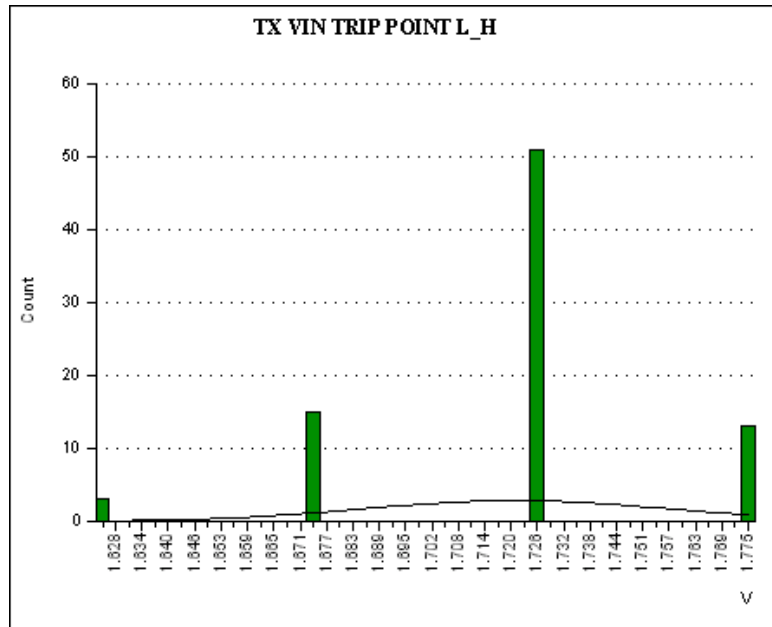
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.002, Test.Name=TX VIN TRIP POINT L_H



Statistics: (V)

Max	1.775	25%	1.725	SpecHigh	N/A
Mean	1.720	10%	1.675	SpecLow	N/A
Min	1.625	N	82	PctWithinSpec	N/A
Range	150.001E-03	Cp	N/A	PctDefSpec	N/A
StdDev	34.792E-03	Cpl	N/A	NWithinSpec	N/A
W	0.7990	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.775	Skew	-0.5425		
75%	1.725	Kurtosis	0.7484		
Median	1.725				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

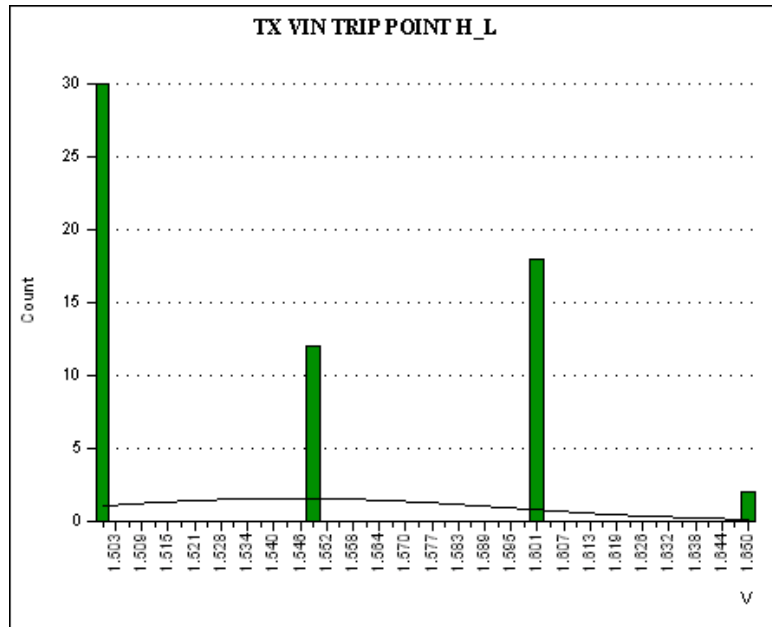
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.003, Test.Name=TX VIN TRIP POINT H_L



Statistics: (V)

Max	1.650	25%	1.500	SpecHigh	N/A
Mean	1.544	10%	1.500	SpecLow	N/A
Min	1.500	N	62	PctWithinSpec	N/A
Range	150.000E-03	Cp	N/A	PctDefSpec	N/A
StdDev	47.463E-03	Cpl	N/A	NWithinSpec	N/A
W	0.7781	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.600	Skew	0.5032		
75%	1.600	Kurtosis	-1.2018		
Median	1.550				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

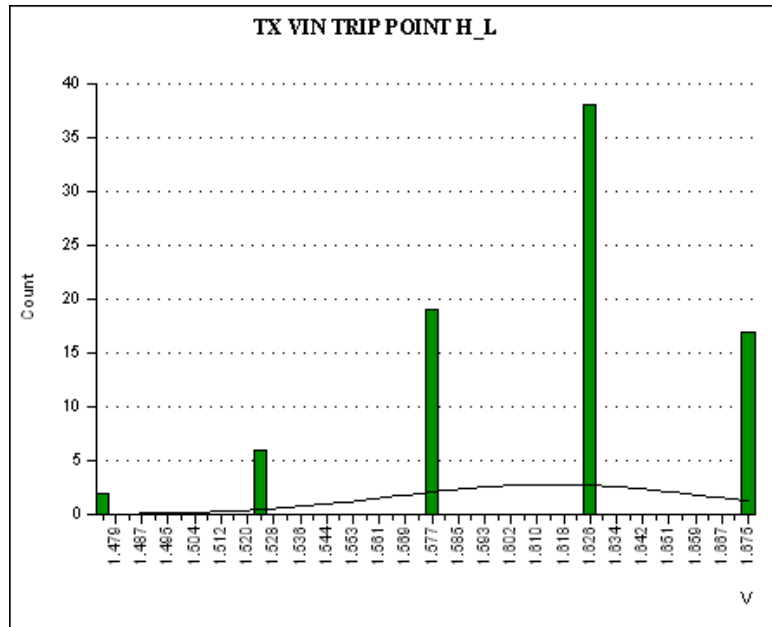
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.003, Test.Name=TX VIN TRIP POINT H_L



Statistics: (V)

Max	1.675	25%	1.575	SpecHigh	N/A
Mean	1.613	10%	1.575	SpecLow	N/A
Min	1.475	N	82	PctWithinSpec	N/A
Range	200.000E-03	Cp	N/A	PctDefSpec	N/A
StdDev	47.506E-03	Cpl	N/A	NWithinSpec	N/A
W	0.8649	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.675	Skew	-0.7275		
75%	1.625	Kurtosis	0.4667		
Median	1.625				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

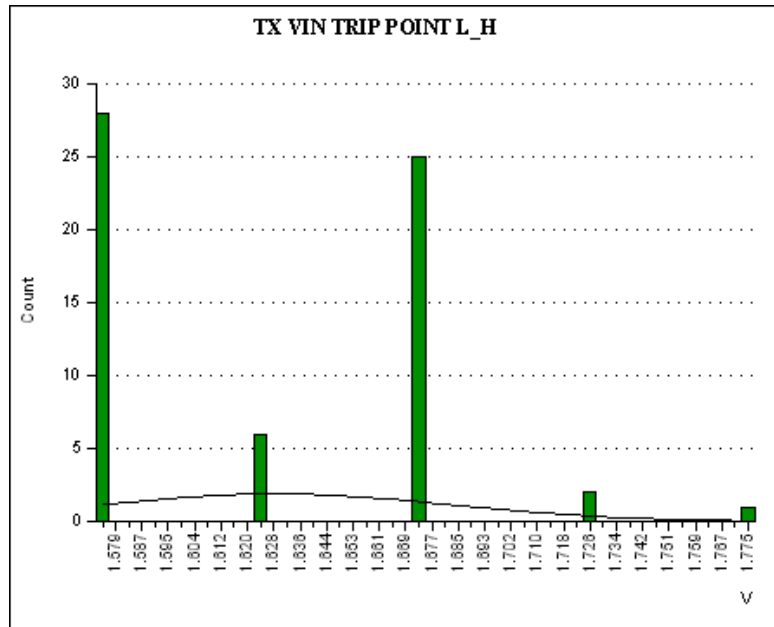
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.004, Test.Name=TX VIN TRIP POINT L_H



Statistics: (V)

Max	1.775	25%	1.575	SpecHigh	N/A
Mean	1.628	10%	1.575	SpecLow	N/A
Min	1.575	N	62	PctWithinSpec	N/A
Range	200.000E-03	Cp	N/A	PctDefSpec	N/A
StdDev	53.463E-03	Cpl	N/A	NWithinSpec	N/A
W	0.7761	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.675	Skew	0.3670		
75%	1.675	Kurtosis	-0.9750		
Median	1.625				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

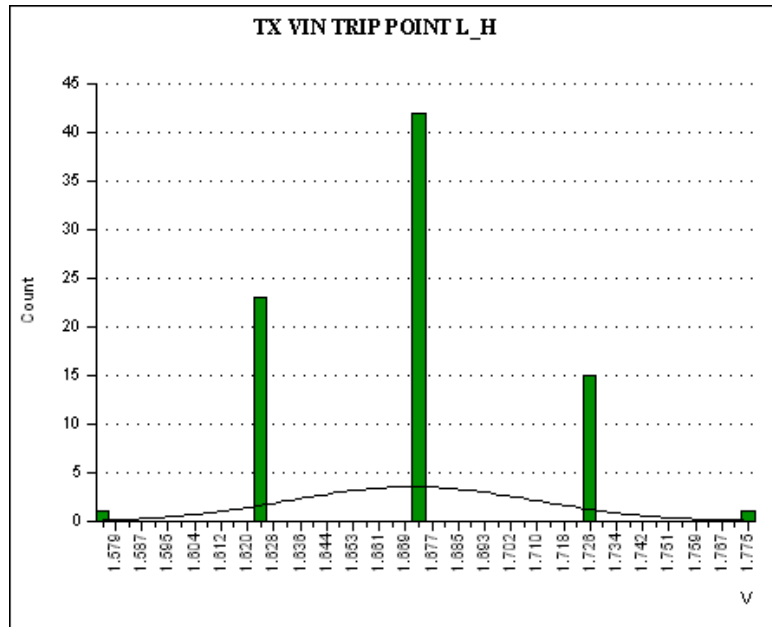
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.004, Test.Name=TX VIN TRIP POINT L_H



Statistics: (V)

Max	1.775	25%	1.625	SpecHigh	N/A
Mean	1.670	10%	1.625	SpecLow	N/A
Min	1.575	N	82	PctWithinSpec	N/A
Range	200.000E-03	Cp	N/A	PctDefSpec	N/A
StdDev	37.359E-03	Cpl	N/A	NWithinSpec	N/A
W	0.8493	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.725	Skew	0.1611		
75%	1.675	Kurtosis	-0.1504		
Median	1.675				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

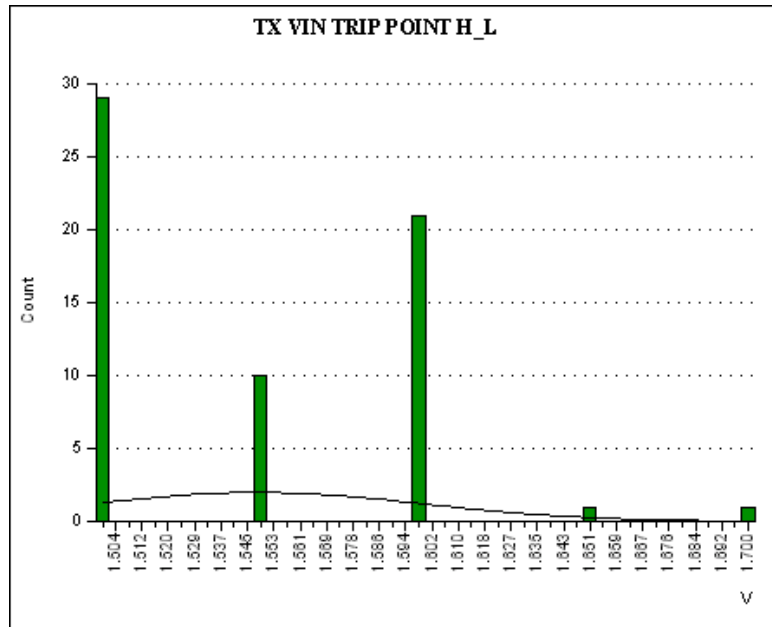
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.005, Test.Name=TX VIN TRIP POINT H_L



Statistics: (V)

Max	1.700	25%	1.500	SpecHigh	N/A
Mean	1.548	10%	1.500	SpecLow	N/A
Min	1.500	N	62	PctWithinSpec	N/A
Range	200.000E-03	Cp	N/A	PctDefSpec	N/A
StdDev	50.754E-03	Cpl	N/A	NWithinSpec	N/A
W	0.7812	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.600	Skew	0.5852		
75%	1.600	Kurtosis	-0.5449		
Median	1.550				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

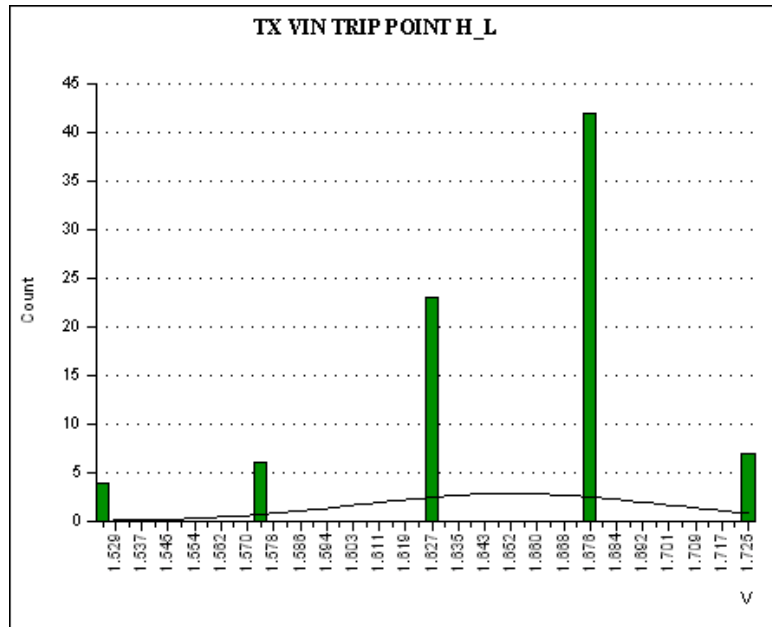
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N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.005, Test.Name=TX VIN TRIP POINT H_L



Statistics: (V)

Max	1.725	25%	1.625	SpecHigh	N/A
Mean	1.651	10%	1.575	SpecLow	N/A
Min	1.525	N	82	PctWithinSpec	N/A
Range	200.000E-03	Cp	N/A	PctDefSpec	N/A
StdDev	46.643E-03	Cpl	N/A	NWithinSpec	N/A
W	0.8347	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.675	Skew	-0.9248		
75%	1.675	Kurtosis	0.9053		
Median	1.675				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

Stat limits applied

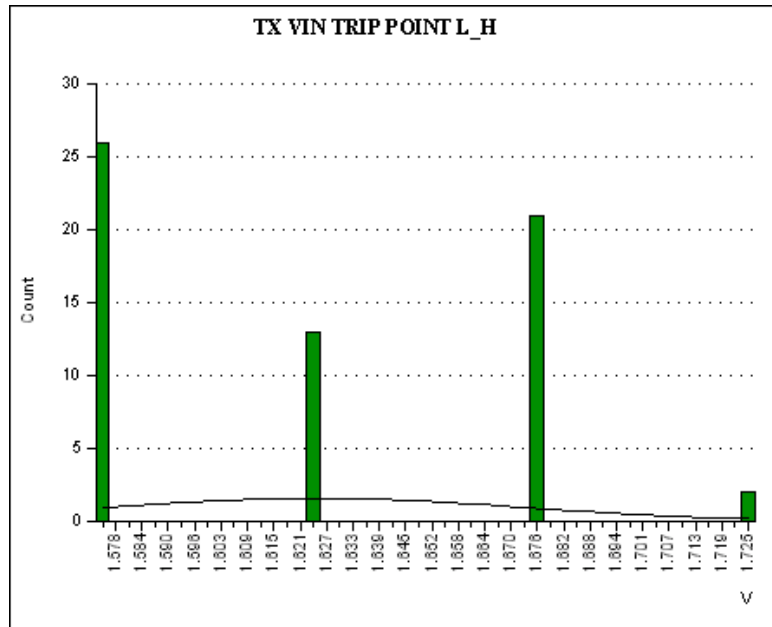
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.006, Test.Name=TX VIN TRIP POINT L_H



Statistics: (V)

Max	1.725	25%	1.575	SpecHigh	N/A
Mean	1.624	10%	1.575	SpecLow	N/A
Min	1.575	N	62	PctWithinSpec	N/A
Range	150.000E-03	Cp	N/A	c	
StdDev	47.470E-03	Cpl	N/A	PctDefSpec	N/A
W	0.7990	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	1.675	Skew	0.2704		
75%	1.675	Kurtosis	-1.3769		
Median	1.625				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

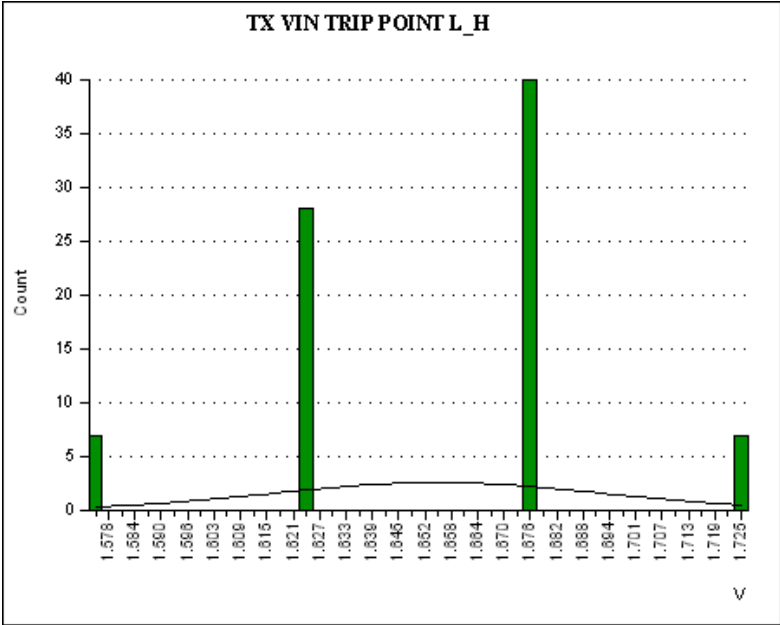
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.006, Test.Name=TX VIN TRIP POINT L_H



Statistics: (V)

Max	1.725	25%	1.625	SpecHigh	N/A
Mean	1.654	10%	1.625	SpecLow	N/A
Min	1.575	N	82	PctWithinSpec	N/A
Range	150.000E-03	Cp	N/A	c	
StdDev	38.514E-03	Cpl	N/A	PctDefSpec	N/A
W	0.8473	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	1.675	Skew	-0.2514		
75%	1.675	Kurtosis	-0.2354		
Median	1.675				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	_	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525H: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0
213L2525R: N/A	SYN440	SP230E	_	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T	-	0

Data: Raw Data

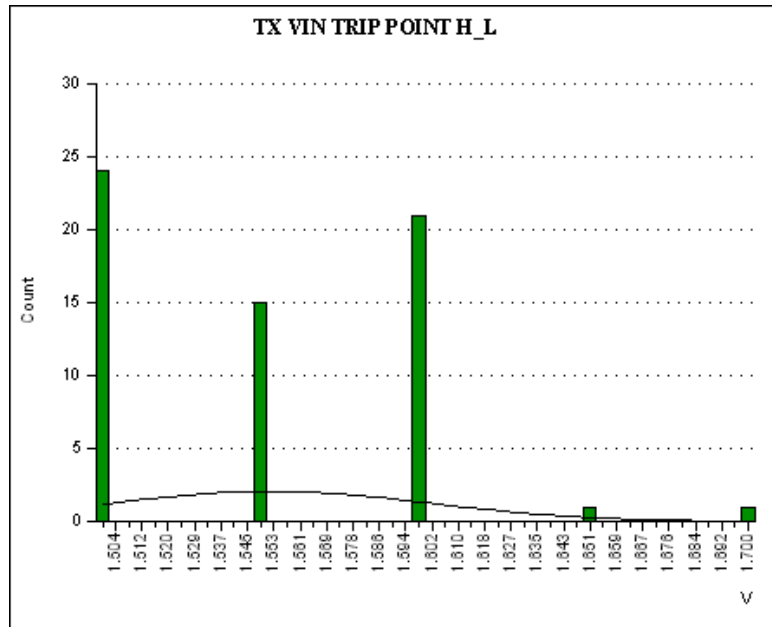
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
N/A

Test.Number=15.007, Test.Name=TX VIN TRIP POINT H_L



Statistics: (V)

Max	1.700	25%	1.500	SpecHigh	N/A
Mean	1.552	10%	1.500	SpecLow	N/A
Min	1.500	N	62	PctWithinSpec	N/A
Range	200.000E-03	Cp	N/A	PctDefSpec	N/A
StdDev	48.728E-03	Cpl	N/A	NWithinSpec	N/A
W	0.8196	Cpu	N/A	NOutsideSpec	N/A
WpValue	0.0000	Cpk	N/A		
90%	1.600	Skew	0.4830		
75%	1.600	Kurtosis	-0.3814		
Median	1.550				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
24634C55C: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55H: N/A	SYN1035	SP213	—	N/A	N/A	N/A	13-APR-2006	N/A	SP213ECH01. AT	-	0
24634C55R: N/A	SYN1035	SP213	—	N/A	N/A	N/A	07-APR-2006	N/A	SP213ECH01. AT	-	0

Data: Raw Data

Stat limits applied

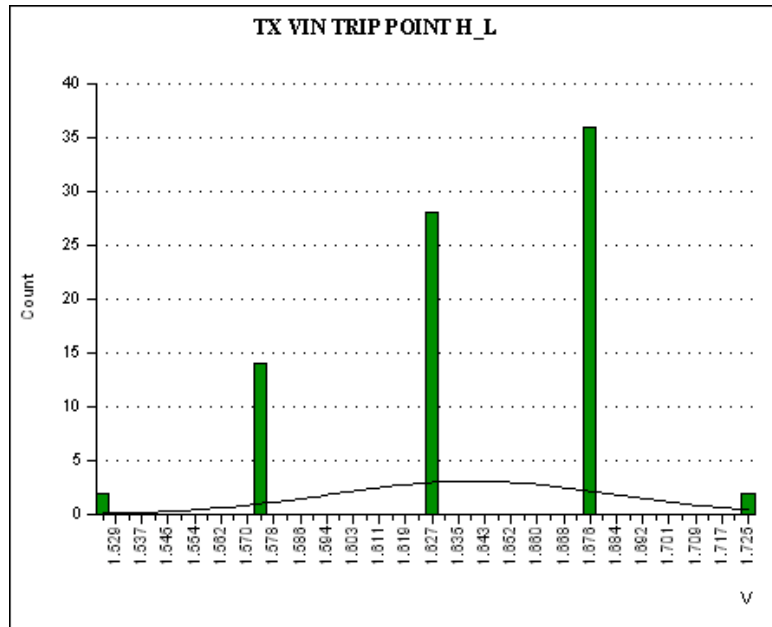
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A

Test.Number=15.007, Test.Name=TX VIN TRIP POINT H_L



Statistics: (V)

Max	1.725	25%	1.625	SpecHigh	N/A
Mean	1.638	10%	1.575	SpecLow	N/A
Min	1.525	N	82	PctWithinSpec	N/A
Range	200.000E-03	Cp	N/A	c	
StdDev	43.068E-03	Cpl	N/A	PctDefSpec	N/A
W	0.8492	Cpu	N/A	NWithinSpec	N/A
WpValue	0.0000	Cpk	N/A	NOutsideSpec	N/A
90%	1.675	Skew	-0.5535		
75%	1.675	Kurtosis	-0.2736		
Median	1.625				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
213L2525C: N/A	SYN440	SP230E	—	N/A	HillView	2um	10-MAR-2036	N/A	SP213ECH.A - T		0
213L2525H: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T		0
213L2525R: N/A	SYN440	SP230E	—	N/A	HillView	2um	05-MAR-2036	N/A	SP213ECH.A - T		0

Data: Raw Data

Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot

N/A